Radiation Report

TPS7H5021-SEP Total Ionizing Dose (TID) Report

ABSTRACT

This report discusses the results of the total ionizing dose (TID) testing for the Texas Instruments TPS7H5021-SEP radiation hardness-assured PWM controller with integrated gate driver. The study was done to determine TID effects at 50krad (Si) High Dose Rate (HDR). The results show that all samples pass within device specified test limits.

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1 Device Information

1.1 Product Description

The TPS7H5021 is a radiation-hardness-assured, current mode, single-ended PWM controller with an integrated gate driver that can be utilized in both silicon and gallium nitride (GaN) power semiconductor based converter designs. The TPS7H5021 integrates several key functions, such as soft-start, enable, and adjustable slope compensation while maintaining a small package size. The controller also features a 0.6V ± 1% voltage reference tolerance to support highly accurate power converter designs. The TPS7H5021-SEP is packaged in a plastic 24-pin HTSSOP PWP package.

1.2 Device Details

Testing was performed per MIL-STD-883, Test Method 1019, with a sample size per MIL-PRF-38535, Appendix C, test condition A (high dose rate).

Table 1-1. Device and Exposure Details

RHA TID Details: Up to 50krad(Si)	
TI Device	TPS7H5021-SEP
TI Part Number	TPS7H5021MPWPTSEP
Device Function	PWM Controller with Integrated Gate Driver
Package	24-pin HTSSOP-PWP
Technology	LBC7 (250nm Linear BiCMOS)
Quantity tested	HDR : • 15 total biased units with 5 units per radiation level from 20krad(Si) to 50krad(Si) • 15 total unbiased units with 5 units per radiation level from 20krad(Si) to 50krad(Si) • Five correlation units
Lot Accept/Reject	Passes up to 50krad(Si); no observed fails
HDR Radiation Facility	Texas Instruments CLAB Dallas, Texas
Die Lot Number and Assembly Lot Number	DIE: 4313716 Assembly: 5306477
HDR Dose Rate	179.97 rad (Si) / s
HDR Radiation Source	Gammacell 220 Excel (GC-220E) Co-60
Irradiation and Test Temperature	Ambient, room temperature controlled to 25°C ±6°C per MIL-STD-883 and MIL-STD-750

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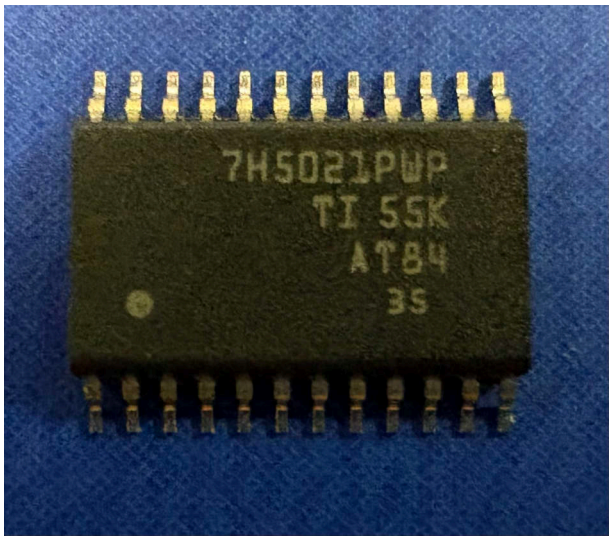

Figure 1-1. Device Used in Exposure (Front)

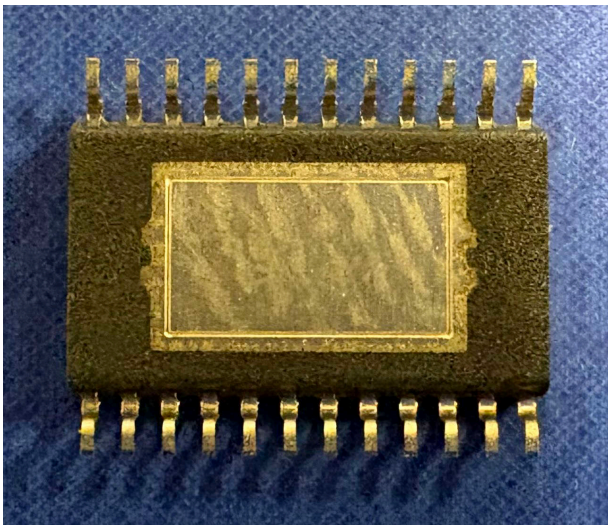

Figure 1-2. Device Used in Exposure (Back)

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2 Total Dose Test Setup

2.1 Test Overview

The TPS7H5021-SEP was tested according to MIL-STD-883, Test Method 1019.9. For this testing, condition A was used. For this test, the product was irradiated up to the target radiation level, and then put through full electrical parametric testing on the production Automated Test Equipment (ATE). All devices remained functional passing all parametric test limits.

2.2 Test Description and Facilities

The TPS7H5021-SEP HDR exposure was performed on biased devices in a Co-60 Gammacell at the TI Dallas C-Lab facility in Dallas, Texas. The unattenuated dose rate of this cell is 179.97 rad (Si) / s. After exposure, the devices were packed in dry ice (per MIL-STD-883 Method 1019.9 section 3.10) and post-radiation electrical testing at TI's Dallas Forest Lane facility. Test limit guard bands are set within SMD electrical test limits.

Post-radiation measurements were taken within 30 minutes after removing device from the dry ice container. The devices were allowed to reach room temperature prior to electrical post-radiation measurements.

2.3 Test Setup Details

The devices under HDR exposure were tested in two conditions, biased and unbiased, as described in the following sections.

2.3.1 Unbiased

For the unbiased HDR conditions, the exposure was performed with all pins grounded.

2.3.2 Biased

For biased testing, the devices were placed in a TID Bias board and irradiated in the radiation chamber. Figure 2-1, Figure 2-2, and Figure 2-3 show the TID board used and socket diagram.

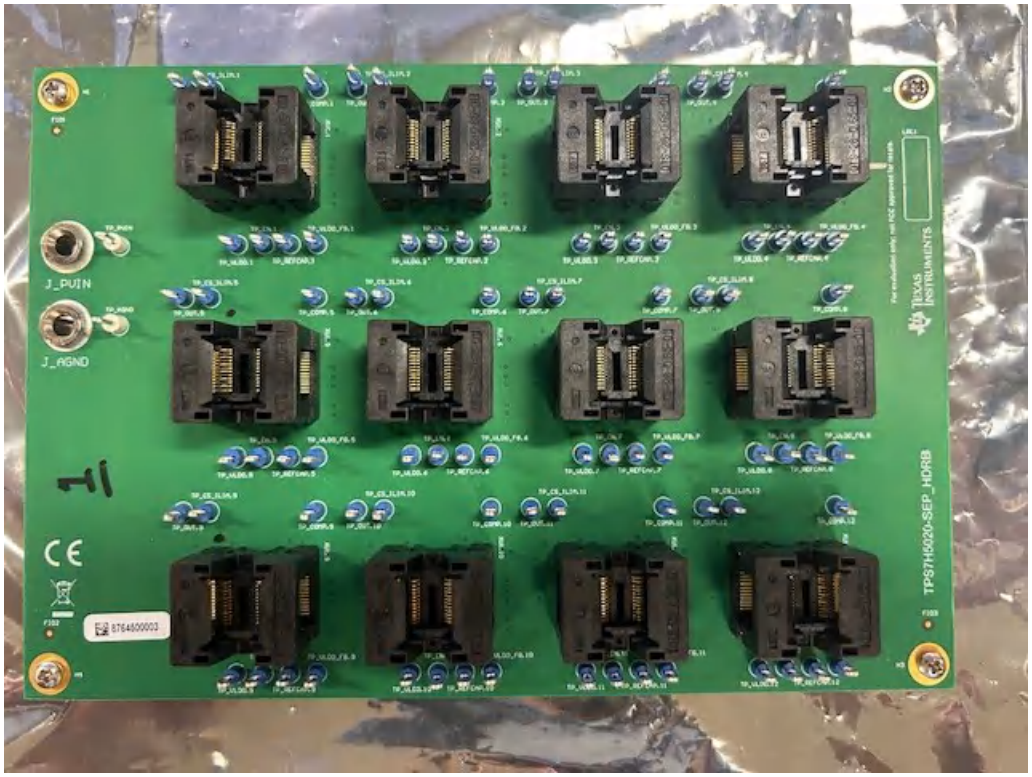

Figure 2-1. HDR TID Hardware

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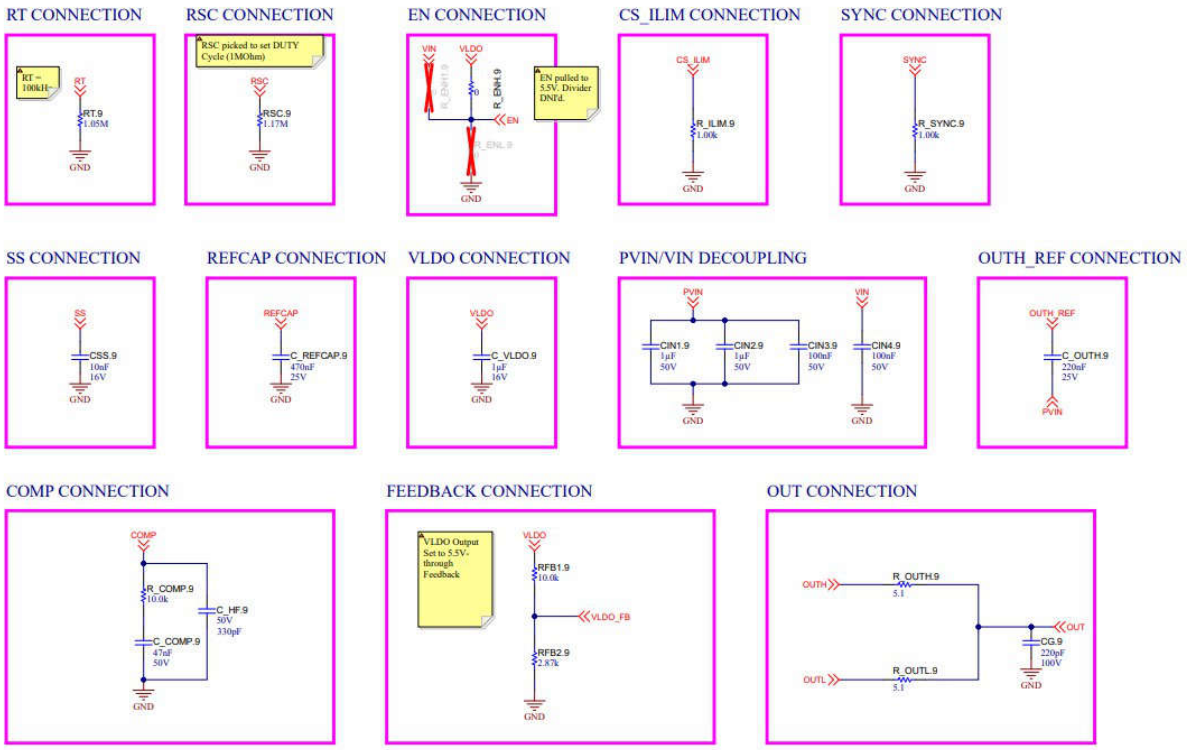

Figure 2-2. Supplies and GND HDR TID Bias Diagram

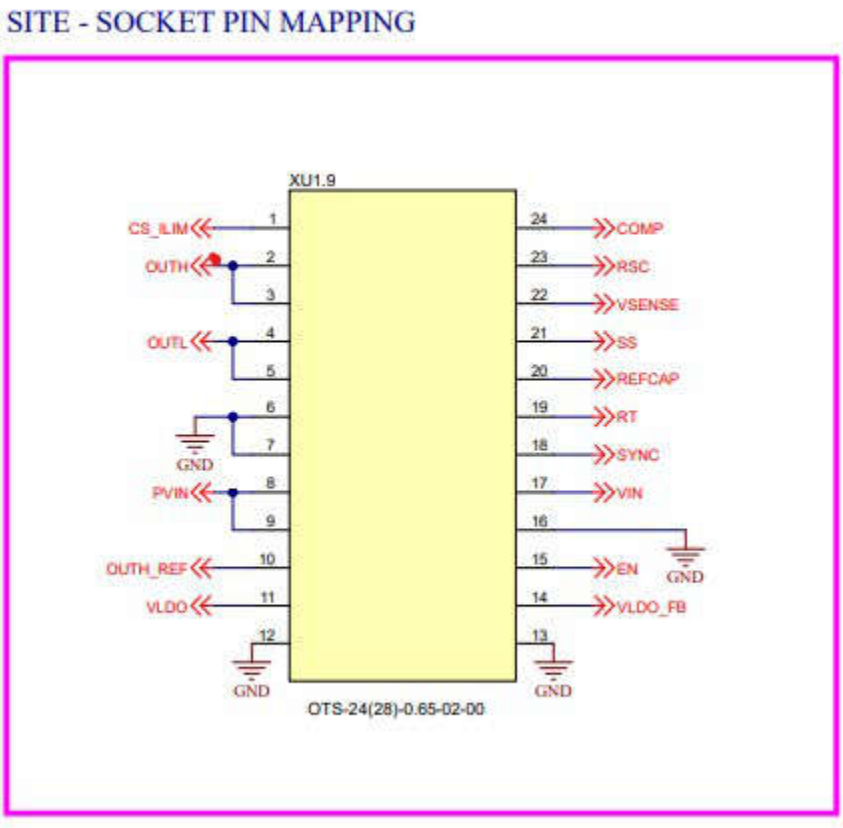

Figure 2-3. HDR TID Bias Diagram

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2.4 Test Configuration and Conditions

HDR devices were stressed up to 50krad (Si) for biased and unbiased conditions.

Table 2-1. HDR Biased Device Information

Total Samples: 15 units + 4 control			
Exposure Levels:			
Control	20krad (Si)	30krad(Si)	50krad (Si)
12, 13, 21, 23	15, 17, 19, 24, 30	6, 11 ,41, 28, 33	1, 3, 7, 10, 26

Table 2-2. HDR Unbiased Device Information

Total Samples: 15 units + 4 control			
Exposure Levels:			
Control	20krad (Si)	30krad(Si)	50krad (Si)
12, 13, 21, 23	2, 9, 16, 18, 35	4, 8, 27, 29, 31	5, 14, 20, 22, 34

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3 TID Characterization Test Results

3.1 TID Characterization Results Summary

The results show that all TPS7H5021-SEP devices were fully functional and within specification limits up to 50krad (Si) HDR. Overall the TPS7H5021-SEP show a strong degree of hardness to TID HDR exposure levels at 50krad (Si) under bias and unbiased conditions. Performance is measured based on the difference between pre- and post-irradiation with respect to SMD electrical minimum and maximum specification. The measurements taken post-irradiation for each sample set showed a marginal shift for most parameters at each dose level for both biased and unbiased. (see Section 3.2 for the electrical parameters). Note that test numbers are listed only for parameters tested post-TID.

See Appendix: HDR TID Report for HDR report.

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3.2 Data Sheet Electrical Parameters

Specifications are at ambient temperature TA = 25°C, PVIN=VIN= 4.5V to 14V unless otherwise noted. Parameters not listed in the table are omitted either because there is no parametric data or because verification was done through bench testing. Parameters without MIN and MAX values are functionally assured by ATE testing.

Table 3-1. TPS7H5021-SEP Data Sheet Electrical Parameters

PARAMETER		TEST CONDITIONS		MIN	MAX	UNIT	Test #
SUPPLY VOLTAGES AND CURRENTS							
IDD	Operating supply current	No load for OUT, PVIN = VIN	fSW = 100kHz		11	mA	14.1, 14.2, 14.3, 14.4
			fSW = 500kHz		17		14.6, 14.8, 14.10, 14.12
			fSW = 1MHz (TPS7H502x)		25		14.14, 14.15, 14.16, 14.17
		CLOAD = 1000pF for OUT, PVIN = VIN	fSW = 100kHz		12	mA	
			fSW = 500kHz		22		
			fSW = 1MHz		28		
		CLOAD = 1000pF for OUT, VIN = 12V, PVIN = VLDO = 5V	fSW = 100kHz		10	mA	14.3
			fSW = 500kHz		13		14.31
			fSW = 1MHz		20		14.32
Istart	Startup current	VIN = 3.5V			5	mA	14.5
IDD(dis)	Standby current	EN = 0V			8	mA	14.7, 14.9, 14.11, 14.13
VLDO	Internal linear regulator output voltage	CVLDO = 1µF	5V ≤ VIN ≤ 14V, RVT = 10kΩ, RVB = 3.74kΩ	4.36	4.62	V	15.1, 15.4, 15.5
			5.5V ≤ VIN ≤ 14V, RVT = 10kΩ, RVB = 3.24kΩ	4.84	5.14		15.8, 15.11, 15.12
			6V ≤ VIN ≤ 14V, RVT = 10 kΩ, RVB = 2.87kΩ	5.31	5.65		15.15, 15.18, 15.19
VLDO_DO	Internal linear dropout voltage	IVLDO = 25mA, CVLDO = 1µF			0.4	V	
I_VLDO	Maximum VLDO output current	VLDO ≥ 96% of VLDO at no load, CVLDO = 1µF	VIN = VLDO + 0.5V	25		mA	
			VIN = VLDO + 1V	55			
			VIN ≥ 7V	90			
ENABLE AND UNDERVOLTAGE LOCKOUT							
VENR	Enable rising threshold			0.57	0.66	V	16.1, 16.4, 16.7, 16.10
VENF	Enable falling threshold			0.48	0.55	V	16.2, 16.5, 16.8, 16.11

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Table 3-1. TPS7H5021-SEP Data Sheet Electrical Parameters (continued)

PARAMETER		TEST CONDITIONS		MIN	MAX	UNIT	Test #
IEN	Enable input leakage current	VIN = 14V	EN = 1V		100	nA	16.15, 16.17
			EN = 7V		700		16.16, 16.18
PVINUVLOR	PVIN UVLO rising			3.65	3.95	V	17.1, 17.10, 17.19
PVINUVLOF	PVIN UVLO falling			3.45	3.75	V	17.2, 17.11, 17.20
VINUVLOR	VIN UVLO rising			3.85	4.15	V	17.4, 17.13, 17.22
VINUVLOF	VIN UVLO falling			3.65	3.95	V	17.5, 17.14, 17.23
VLDOUVLOR	VLDO UVLO rising			3.65	3.95	V	17.7, 17.16, 17.25
VLDOUVLOF	VLDO UVLO falling			3.45	3.75	V	17.8, 17.17, 17.26
SOFT START							
ISS	Soft-start current	SS = 0.3V		2	3.4	µA	18.1, 18.5, 18.9, 18.13, 18.17, 18.21, 18.25, 18.29, 18.33, 18.37, 18.41, 18.45
ERROR AMPLIFIER							
EAgm	Error amplifier transconductance	–10µA < ICOMP < 10µA, V(COMP) = 1V		1100	2700	µA/V	19.1, 19.5, 19.9, 19.13
EAISRC	Error amplifier source current	V(COMP) = 1V, 100mV input overdrive		95	210	µA	19.2, 19.6, 19.10, 19.14
EAISNK	Error amplifier sink current	V(COMP) = 1V, 100mV input overdrive		95	210	µA	19.3, 19.7, 19.11, 19.15
EAOS	Error amplifier input offset voltage			–5	6	mV	19.27, 19.30, 19.33, 19.36, 19.39, 19.42, 19.45, 19.48, 19.51, 19.54, 19.57, 19.60
EAIB	Error amplifier input bias current				25	nA	19.4, 19.8, 19.12, 19.16, 19.17, 19.18, 19.19, 19.20, 19.21, 19.22, 19.23, 19.24
OSCILLATOR							
SYNCIL	SYNC in low-level	VLDO = 4.5V	VIN < 5V		0.8	V	
			VIN ≥ 5V		0.8		
		VLDO = 5.5V	VIN < 6V		0.8	V	
			VIN ≥ 6V		0.8		

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Table 3-1. TPS7H5021-SEP Data Sheet Electrical Parameters (continued)

PARAMETER		TEST CONDITIONS		MIN	MAX	UNIT	Test #
SYNCIH	SYNC in high-level	VLDO = 4.5V	VIN < 5V	3.5		V	
			VIN ≥ 5V	3.5			
		VLDO = 5.5V	VIN < 6V	3.5		V	
			VIN ≥ 6V	3.5			
DSYNC	SYNC in duty cycle	Duty cycle of external clock, f ≥ 200kHz		48%	52%		20.17, 20.18, 20.21, 20.22, 20.25, 20.26, 20.29, 20.30, 20.41, 20.42, 20.45, 20.46, 20.49, 20.50, 20.53, 20.54, 20.57, 20.58, 20.61, 20.62, 20.65, 20.66, 20.69, 20.70
		Duty cycle of external clock, 100kHz ≤ f < 200kHz		49%	51%		
DTINT	External clock to internal clock detection time	RT populated			5	(1/fsw) s	20.144, 20.146, 20.148, 20.150, 20.152, 20.154, 20.156, 20.158, 20.160, 20.162, 20.164, 20.166, 20.168, 20.170, 20.172, 20.174
DTEXT	Internal clock to external clock detection time	RT populated			5	(1/fsw) s	20.112, 20.114, 20.116, 20.118, 20.120, 20.122, 20.124, 20.126, 20.128, 20.130, 20.132, 20.134, 20.136, 20.138, 20.140, 20.142
fSW	RT programmed switching frequency	RT = 1.18MΩ		80	110	kHz	20.15, 20.19, 20.23, 20.27, 20.71, 20.73, 20.75, 20.77
		RT = 560kΩ		175	220	kHz	20.31, 20.33, 20.35, 20.37, 20.79, 20.81, 20.83, 20.85
		RT = 210kΩ		450	550	kHz	20.39, 20.43, 20.47, 20.51, 20.87, 20.89, 20.91, 20.93
fSW	RT programmed switching frequency	RT = 100kΩ		925	1100	kHz	20.55, 20.59, 20.63, 20.67, 20.95, 20.97, 20.99, 20.101

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Table 3-1. TPS7H5021-SEP Data Sheet Electrical Parameters (continued)

PARAMETER		TEST CONDITIONS		MIN	MAX	UNIT	Test #
VOLTAGE REFERENCE							
VREF	Internal voltage reference	Measured at COMP, COMP = VSENSE	TA = 25°C	0.597	0.603	V	19.25, 19.28, 19.31, 19.34, 19.37, 19.40, 19.43, 19.46, 19.49, 19.52, 19.55, 19.58, 19.61, 19.63, 19.65, 19.67, 19.69, 19.71, 19.73, 19.75, 19.77, 19.79, 19.81, 19.83
			TA = –55°C	0.594	0.602		
			TA = 125°C	0.597	0.604		
REFCAP	REFCAP voltage	CREFCAP = 470nF		1.208	1.235	V	21.1, 21.3, 21.5, 21.7, 21.9, 21.11, 21.13, 21.15, 21.17, 21.19, 21.21, 21.23, 21.25, 21.27, 21.29, 21.31, 21.33, 21.35, 21.37, 21.39, 21.41, 21.43, 21.45, 21.47
CURRENT SENSE							
CCSR	COMP to CS_ILIM ratio	RSC = open		1.94	2.06		28.1, 28.2, 28.3, 28.4
VCS_ILIM	Current limit (overcurrent) threshold			0.96	1.04	V	28.9, 28.10, 28.11, 28.12, 28.13, 28.14, 28.15, 28.16, 28.17, 28.18, 28.19, 28.20
	CS_ILIM to OUT delay	CS_ILIM = 1V to 90% of OUT falling			115	ns	28.21, 28.22, 28.23, 28.24, 28.25, 28.26, 28.27, 28.28
GATE DRIVER							
VOL	Low-level voltage	IOL = 50mA			0.15	V	24.1, 24.3, 24.5, 24.7
PVIN - VOH	High-level voltage	IOH = 50mA			0.25	V	24.2, 24.4, 24.6, 24.8
tR_OUT	OUT rise time	CLOAD = 1000pF, 10% to 90%	VIN = PVIN = 4.5V		14	ns	24.9
			VIN = PVIN = 5V		14		24.11

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Table 3-1. TPS7H5021-SEP Data Sheet Electrical Parameters (continued)

PARAMETER		TEST CONDITIONS		MIN	MAX	UNIT	Test #
tR_OUT	OUT rise time	CLOAD = 1000pF, 10% to 90%	VIN = PVIN = 12V		18	ns	24.13
			VIN = PVIN = 14V		20		24.15
tR_OUT	OUT rise time	CLOAD = 1000pF, 10% to 90%	VIN = 12V, PVIN = VLDO		16	ns	24.17, 24.19, 24.21
		CLOAD = 220pF, 10% to 90%	VIN = 12V, PVIN = VLDO		12	ns	24.23, 24.25, 24.27
tF_OUT	OUT fall time	CLOAD = 1000pF, 90% to 10%	VIN = PVIN = 4.5V		14	ns	24.1
			VIN = PVIN = 5V		14		24.12
tF_OUT	OUT fall time	CLOAD = 1000pF, 90% to 10%	VIN = PVIN = 12V		18	ns	24.14
			VIN = PVIN = 14V		18		24.16
tF_OUT	OUT fall time	CLOAD = 1000pF, 90% to 10%	VIN = 12V, PVIN = VLDO		14	ns	24.18, 24.20, 24.22
		CLOAD = 220pF, 90% to 10%	VIN = 12V, PVIN = VLDO		10	ns	24.24, 24.26, 24.28
ROH	Pull-up resistance	100mA from OUT			4.7	Ω	23.5, 23.7, 23.9, 23.11
ROL	Pull-down resistance	100mA into OUT			2.8	Ω	23.6, 23.8, 23.10, 23.12
VUCLAMP	Unpowered OUT clamp voltage	Switching disabled, 1mA pull-up applied to OUT	PVIN = 0V		1	V	24.29
			0V < PVIN < 5V		2.5		24.3
PWM AND DUTY CYCLE							
TLEB	Leading edge blank time	5V ≤ VIN ≤ 14V, 10% of OUT rising to end of blanking			80	ns	25.1, 25.4, 25.7
ton_min	Minimum on-time(5)				165	ns	26.1, 26.2, 26.3, 26.4
toff_min	Minimum off-time				70	ns	26.5, 26.7

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Table 3-1. TPS7H5021-SEP Data Sheet Electrical Parameters (continued)

PARAMETER		TEST CONDITIONS	MIN	MAX	UNIT	Test #
DMAX	Maximum duty cycle		42%	50%		27.17, 27.18, 27.19, 27.20, 27.21, 27.22, 27.23, 27.24, 27.25, 27.26, 27.27, 27.28, 27.29, 27.30, 27.31, 27.32, 27.33, 27.34, 27.35, 27.36, 27.37, 27.38, 27.39, 27.40, 27.41, 27.42, 27.43, 27.44, 27.45, 27.46, 27.47, 27.48

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4 Applicable and Reference Documents

4.1 Applicable Documents

- Texas Instruments, *TPS7H502x-SP and TPS7H502x-SEP Radiation-Hardened 1MHz Current Mode PWM Controller With Integrated Gate Driver*, data sheet
- Texas Instruments, *TPS7H5020-SP Evaluation Module*, EVM user's guide.

4.2 Reference Documents

Texas Instruments total ionizing dose radiation (total dose) test procedure follows the standards put forth in MIL-STD-883 TM 1019. The document can be found at the DLA website.

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A Appendix: HDR TID Report

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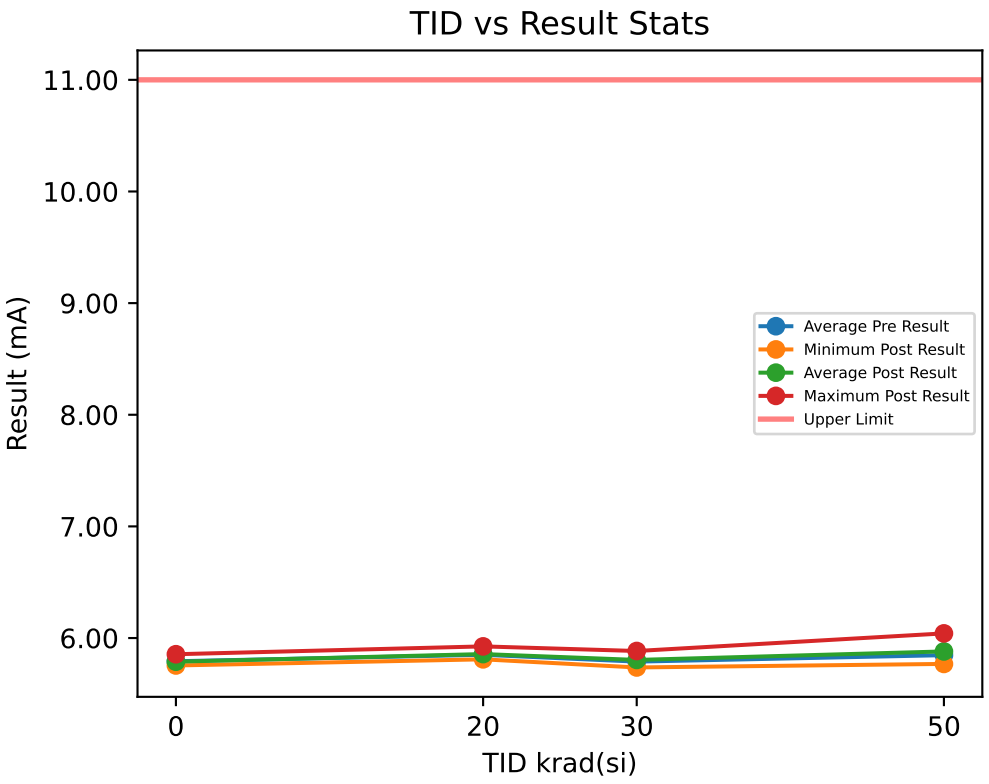
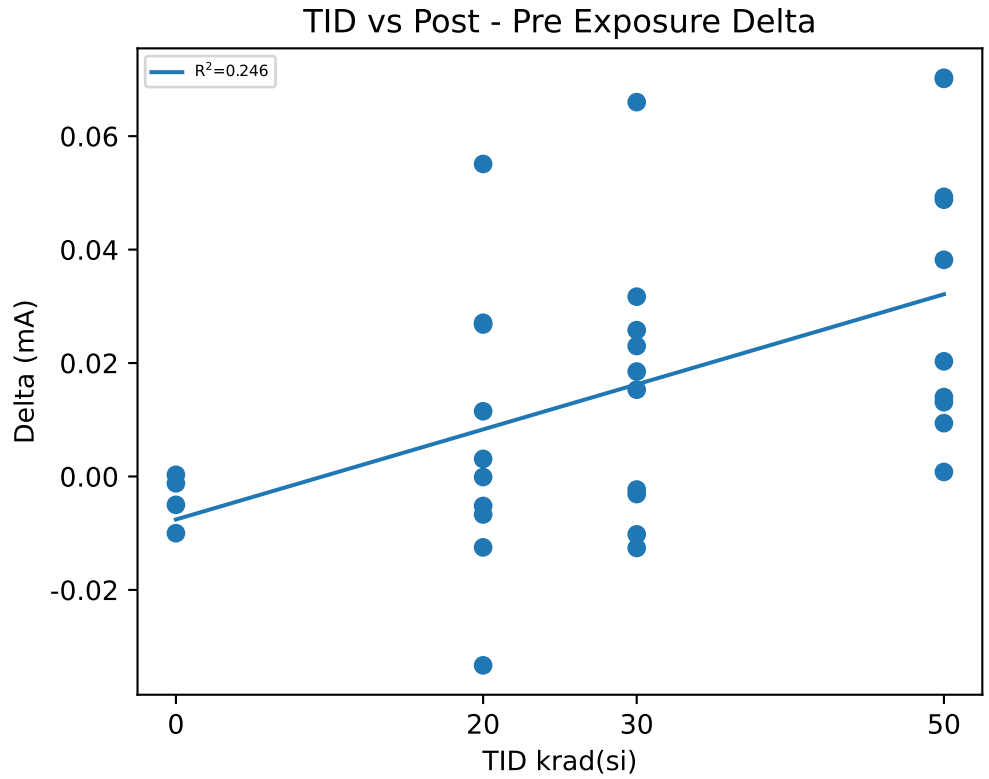
Device Test: 14.1 IDD|SUPPLY CURRENT/IN/4.5/4.5/0/0/4.5/100kHz//@IDD_ACT_100K_NOLOAD





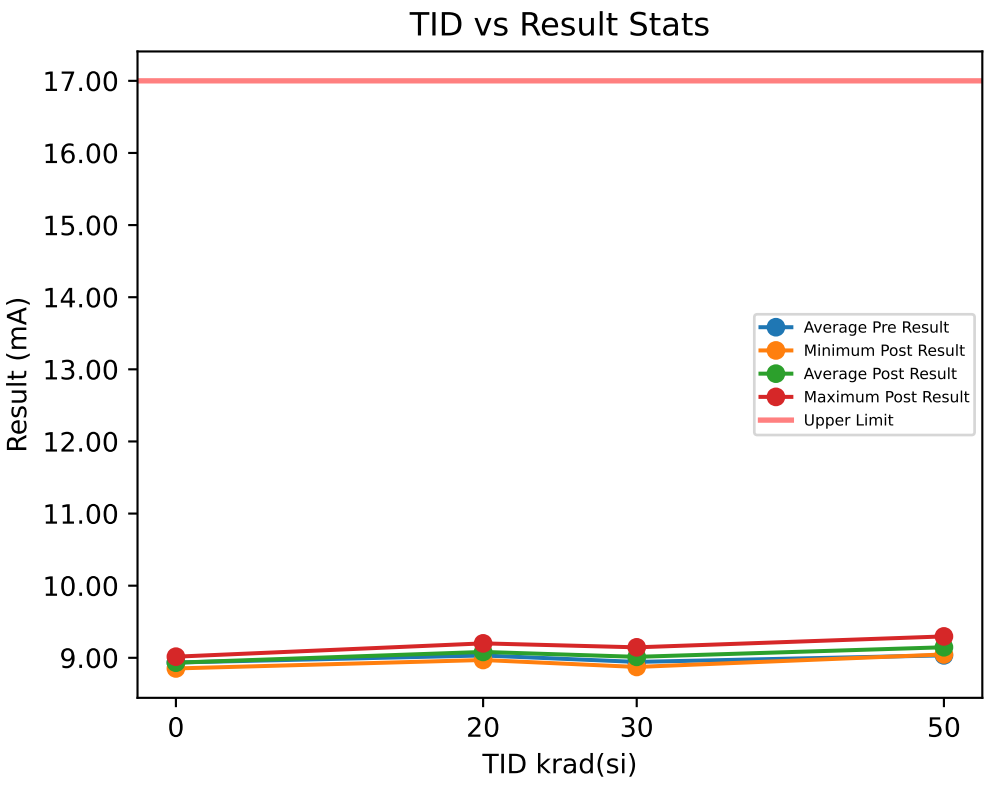
Test Results (Upper Limit = 11.0 (mA))

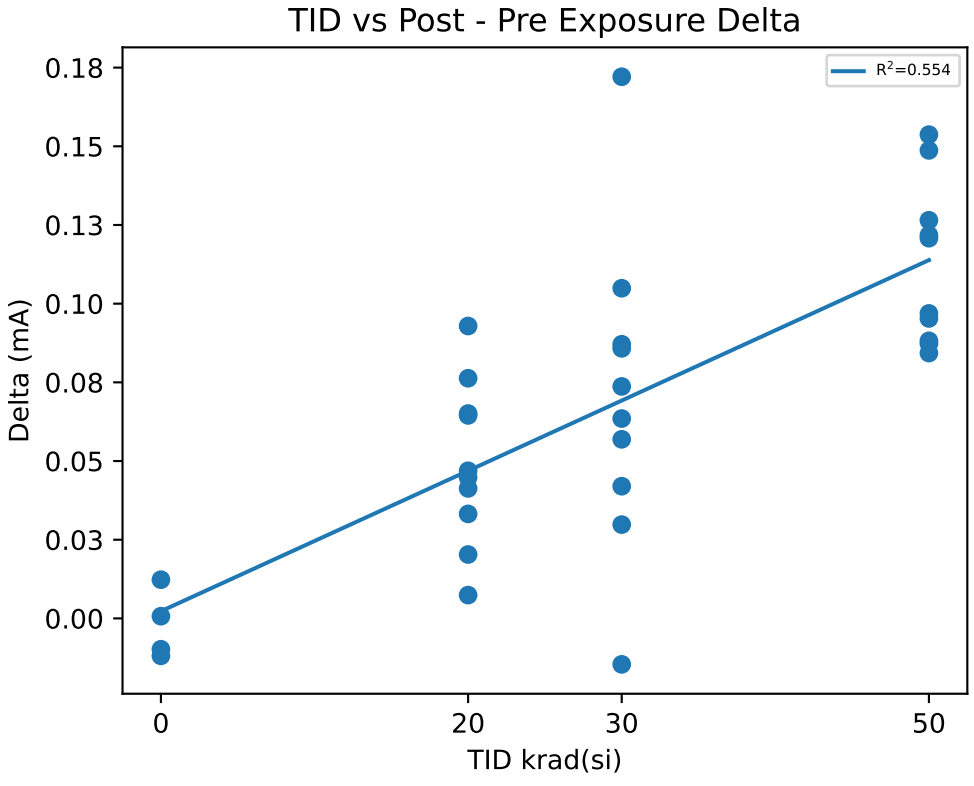
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	5.7878	5.8018	0.014
2	20	Unbiased	5.8251	5.8126	-0.0125
3	50	Biased	5.7551	5.7682	0.0131
4	30	Unbiased	5.7998	5.8315	0.0317
5	50	Unbiased	5.8567	5.877	0.0203
6	30	Biased	5.7606	5.7864	0.0258
7	50	Biased	5.9104	5.9597	0.0493
8	30	Unbiased	5.8686	5.8839	0.0153
9	20	Unbiased	5.8225	5.8776	0.0551
10	50	Biased	5.8134	5.8622	0.0488
11	30	Biased	5.7404	5.7381	-0.0023
12	0	Correlation	5.7866	5.7869	0.0003
13	0	Correlation	5.8649	5.8549	-0.01
14	50	Unbiased	5.922	5.9314	0.0094
15	20	Biased	5.8398	5.8346	-0.0052
16	20	Unbiased	5.8586	5.8701	0.0115
17	20	Biased	5.8984	5.9252	0.0268
18	20	Unbiased	5.8726	5.8659	-0.0067
19	20	Biased	5.8263	5.8262	-0.0001
20	50	Unbiased	5.9713	6.0416	0.0703
21	0	Correlation	5.7593	5.7543	-0.005
22	50	Unbiased	5.781	5.8511	0.0701
23	0	Correlation	5.7574	5.7562	-0.0012
24	20	Biased	5.8062	5.8093	0.0031
26	50	Biased	5.8034	5.8416	0.0382
27	30	Unbiased	5.8732	5.8606	-0.0126
28	30	Biased	5.8602	5.8787	0.0185
29	30	Unbiased	5.759	5.7488	-0.0102
30	20	Biased	5.8283	5.8554	0.0271
31	30	Unbiased	5.7396	5.7365	-0.0031
33	30	Biased	5.7956	5.8186	0.023
34	50	Unbiased	5.8652	5.866	0.0008
35	20	Unbiased	5.9211	5.8878	-0.0333
41	30	Biased	5.6902	5.7562	0.066

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.7574	5.792	5.8649	0.050365	5.7543	5.7881	5.8549	0.046988	-0.01	-0.003975	0.0003	0.0045945
20	5.8062	5.8499	5.9211	0.037139	5.8093	5.8565	5.9252	0.036472	-0.0333	0.00658	0.0551	0.024798
30	5.6902	5.7887	5.8732	0.062294	5.7365	5.8039	5.8839	0.058384	-0.0126	0.01521	0.066	0.023796
50	5.7551	5.8466	5.9713	0.070597	5.7682	5.8801	6.0416	0.079271	0.0008	0.03343	0.0703	0.02543

Device Test: 14.10 IDD|SUPPLY CURRENT/IN/12/12/0/0/5/500kHz//@IDD_ACT_500K_NOLOAD





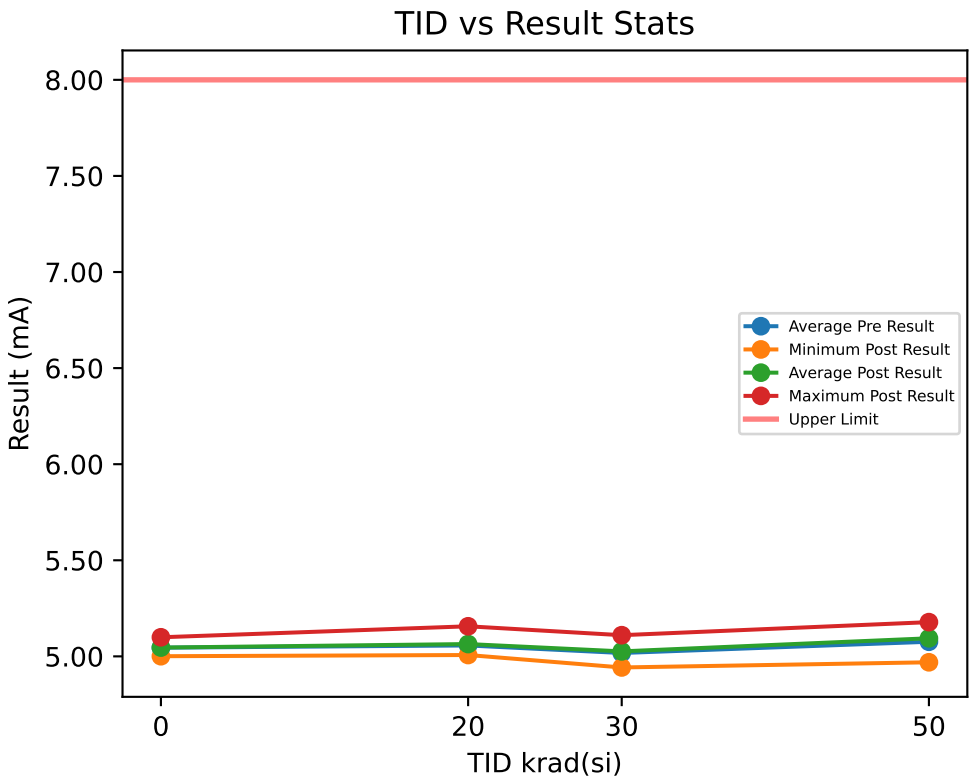
Test Results (Upper Limit = 17.0 (mA))

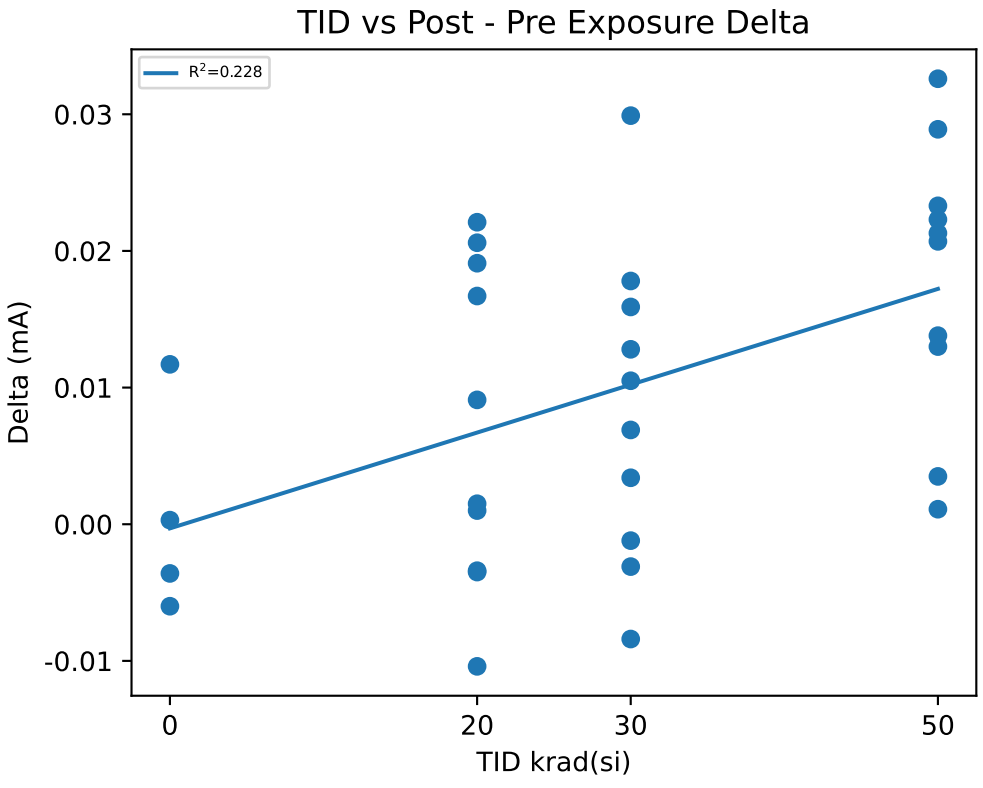
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	8.9594	9.0467	0.0873
2	20	Unbiased	9.0763	9.1211	0.0448
3	50	Biased	8.9924	9.0767	0.0843
4	30	Unbiased	9.0404	9.1453	0.1049
5	50	Unbiased	9.0082	9.1035	0.0953
6	30	Biased	8.9263	9.0121	0.0858
7	50	Biased	9.085	9.2068	0.1218
8	30	Unbiased	9.0624	9.1361	0.0737
9	20	Unbiased	8.9631	9.056	0.0929
10	50	Biased	8.9968	9.1176	0.1208
11	30	Biased	8.8824	8.9122	0.0298
12	0	Correlation	8.8401	8.8524	0.0123
13	0	Correlation	9.015	9.0157	0.0007
14	50	Unbiased	9.1228	9.211	0.0882
15	20	Biased	8.9495	8.9698	0.0203
16	20	Unbiased	9.0586	9.1349	0.0763
17	20	Biased	9.0394	9.1045	0.0651
18	20	Unbiased	9.0792	9.1205	0.0413
19	20	Biased	9.0474	9.0806	0.0332
20	50	Unbiased	9.148	9.2967	0.1487
21	0	Correlation	8.9437	8.9339	-0.0098
22	50	Unbiased	8.9594	9.1131	0.1537
23	0	Correlation	8.9396	8.9277	-0.0119
24	20	Biased	8.9528	8.9997	0.0469
26	50	Biased	8.9771	9.074	0.0969
27	30	Unbiased	8.9597	9.0017	0.042
28	30	Biased	9.0242	9.1113	0.0871
29	30	Unbiased	8.9823	9.0392	0.0569
30	20	Biased	8.9642	9.0287	0.0645
31	30	Unbiased	8.8878	8.8732	-0.0146
33	30	Biased	8.8634	8.9269	0.0635
34	50	Unbiased	9.0903	9.2168	0.1265
35	20	Unbiased	9.1928	9.2002	0.0074
41	30	Biased	8.8029	8.975	0.1721

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	8.8401	8.9346	9.015	0.071885	8.8524	8.9324	9.0157	0.066741	-0.0119	-0.002175	0.0123	0.011113
20	8.9495	9.0323	9.1928	0.077077	8.9698	9.0816	9.2002	0.069255	0.0074	0.04927	0.0929	0.025941
30	8.8029	8.9432	9.0624	0.085063	8.8732	9.0133	9.1453	0.095275	-0.0146	0.07012	0.1721	0.049407
50	8.9594	9.0339	9.148	0.070553	9.0467	9.1463	9.2967	0.081094	0.0843	0.11235	0.1537	0.025645

Device Test: 14.11 IDD_DIS|STANDBY CURRENT/IN/12/12/0/0/5/500kHz//@IDD_DIS





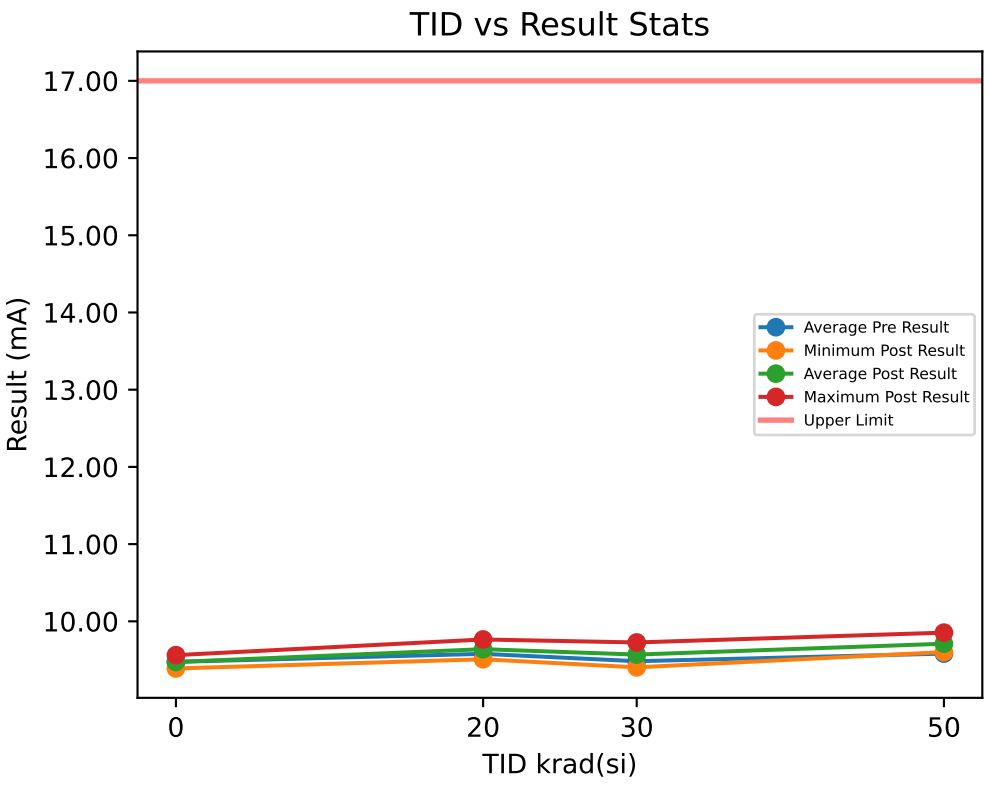
Test Results (Upper Limit = 8.0 (mA))

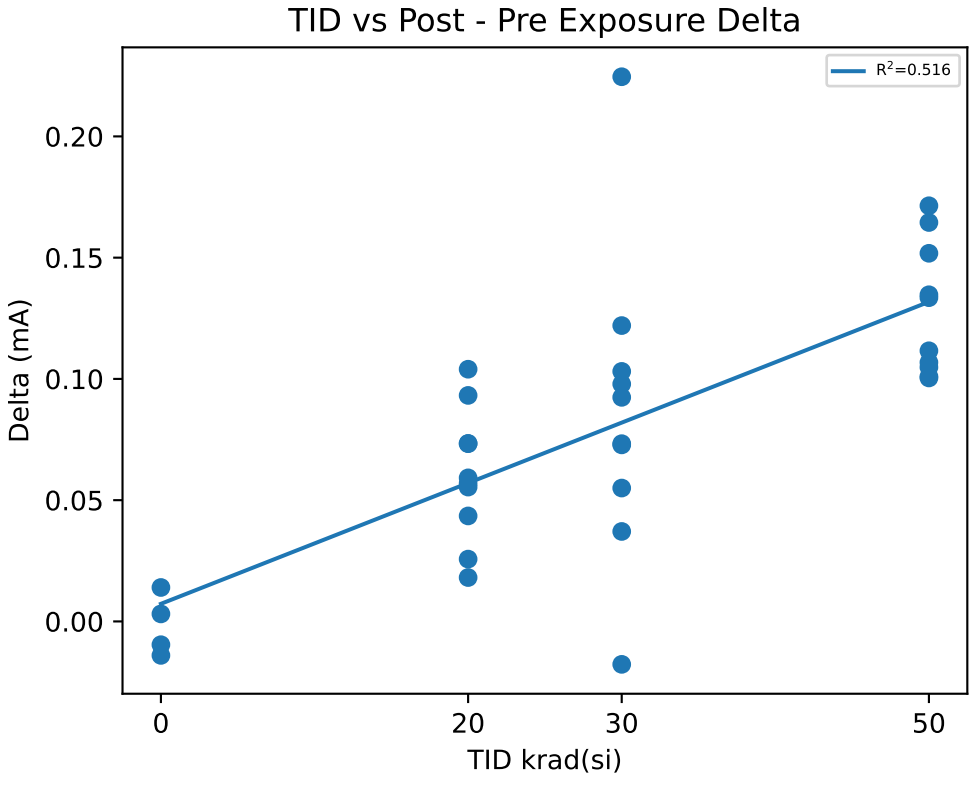
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	5.0369	5.0499	0.013
2	20	Unbiased	5.051	5.0406	-0.0104
3	50	Biased	4.9657	4.9692	0.0035
4	30	Unbiased	5.0204	5.0503	0.0299
5	50	Unbiased	5.0818	5.1041	0.0223
6	30	Biased	5.0314	5.0383	0.0069
7	50	Biased	5.1019	5.1308	0.0289
8	30	Unbiased	5.0924	5.1102	0.0178
9	20	Unbiased	4.9903	5.007	0.0167
10	50	Biased	5.0356	5.0367	0.0011
11	30	Biased	4.9389	4.9423	0.0034
12	0	Correlation	4.9964	5.0081	0.0117
13	0	Correlation	5.1053	5.0993	-0.006
14	50	Unbiased	5.1017	5.1155	0.0138
15	20	Biased	5.0148	5.0158	0.001
16	20	Unbiased	5.1025	5.1246	0.0221
17	20	Biased	5.0901	5.1107	0.0206
18	20	Unbiased	5.055	5.0565	0.0015
19	20	Biased	5.0215	5.0181	-0.0034
20	50	Unbiased	5.1455	5.1781	0.0326
21	0	Correlation	5.0786	5.075	-0.0036
22	50	Unbiased	5.0607	5.082	0.0213
23	0	Correlation	5.0005	5.0008	0.0003
24	20	Biased	5.0158	5.0349	0.0191
26	50	Biased	5.0819	5.1026	0.0207
27	30	Unbiased	5.0674	5.0662	-0.0012
28	30	Biased	5.0453	5.0581	0.0128
29	30	Unbiased	4.9731	4.9647	-0.0084
30	20	Biased	5.0669	5.076	0.0091
31	30	Unbiased	4.9914	4.9883	-0.0031
33	30	Biased	5.0175	5.028	0.0105
34	50	Unbiased	5.1484	5.1717	0.0233
35	20	Unbiased	5.16	5.1565	-0.0035
41	30	Biased	4.9976	5.0135	0.0159

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9964	5.0452	5.1053	0.055097	5.0008	5.0458	5.0993	0.048858	-0.006	0.0006	0.0117	0.0078422
20	4.9903	5.0568	5.16	0.050662	5.007	5.0641	5.1565	0.051298	-0.0104	0.00728	0.0221	0.011759
30	4.9389	5.0175	5.0924	0.045094	4.9423	5.026	5.1102	0.050357	-0.0084	0.00845	0.0299	0.011375
50	4.9657	5.076	5.1484	0.054806	4.9692	5.0941	5.1781	0.063289	0.0011	0.01805	0.0326	0.010194

Device Test: 14.12 IDD|SUPPLY CURRENT/IN/14/14/0/0/5/500kHz//@IDD_ACT_500K_NOLOAD





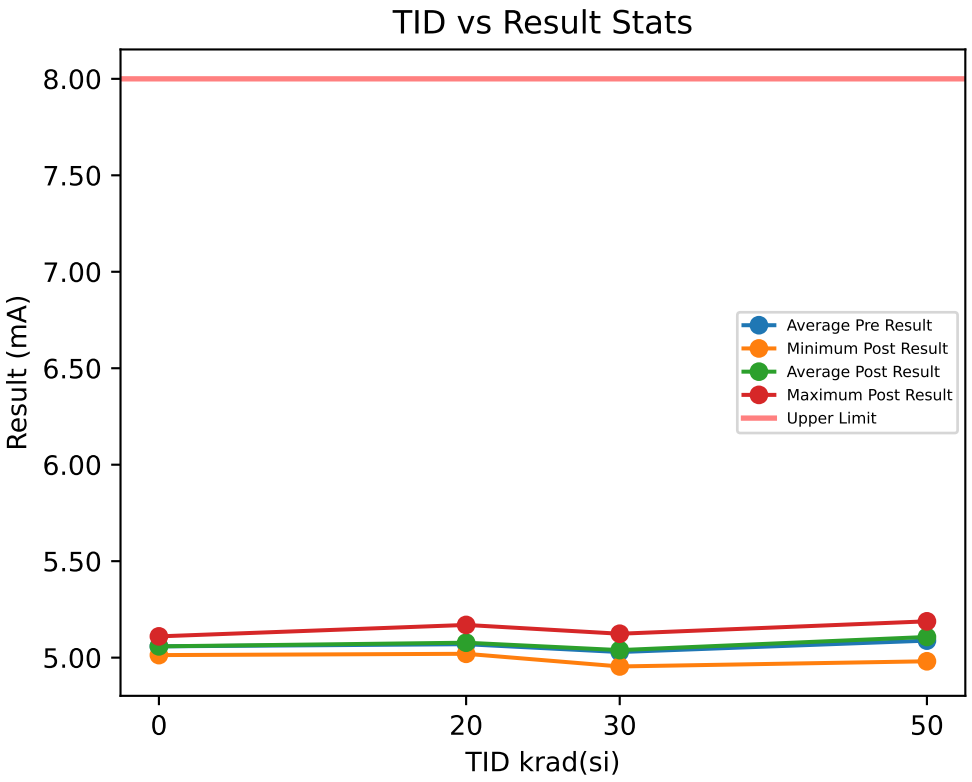
Test Results (Upper Limit = 17.0 (mA))

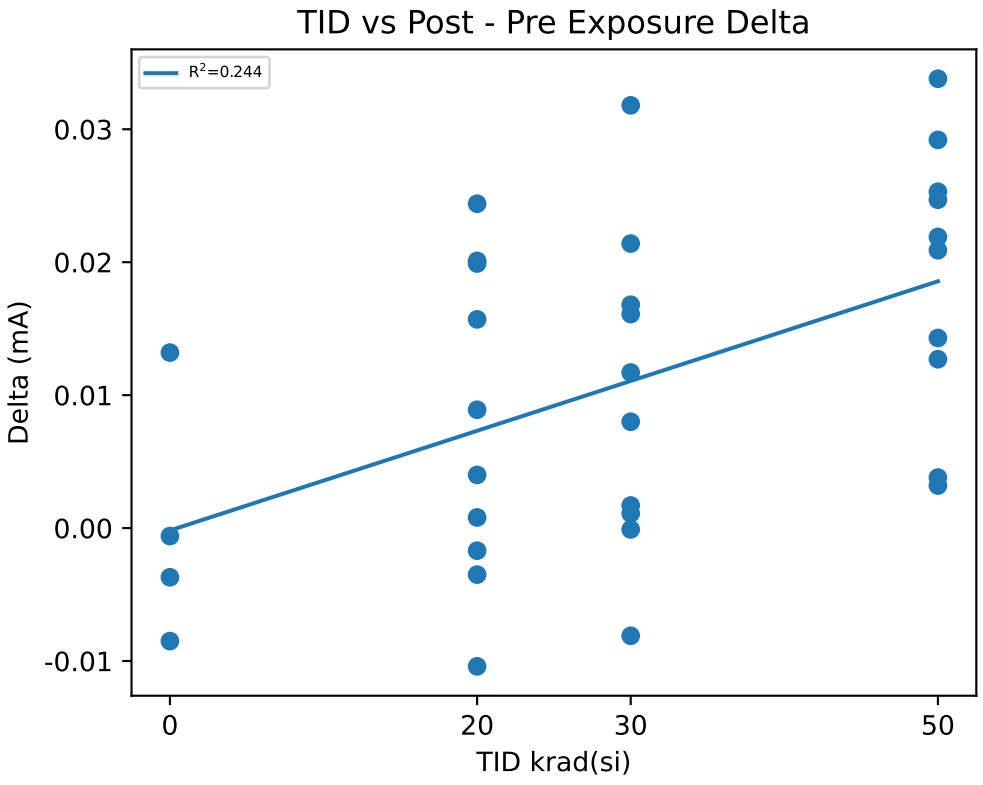
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	9.501	9.6014	0.1004
2	20	Unbiased	9.6284	9.6876	0.0592
3	50	Biased	9.5433	9.6443	0.101
4	30	Unbiased	9.6043	9.7263	0.122
5	50	Unbiased	9.5464	9.6532	0.1068
6	30	Biased	9.4713	9.5692	0.0979
7	50	Biased	9.6269	9.7616	0.1347
8	30	Unbiased	9.6146	9.707	0.0924
9	20	Unbiased	9.5085	9.6125	0.104
10	50	Biased	9.5655	9.699	0.1335
11	30	Biased	9.4145	9.4516	0.0371
12	0	Correlation	9.3756	9.3896	0.014
13	0	Correlation	9.5591	9.5622	0.0031
14	50	Unbiased	9.684	9.7888	0.1048
15	20	Biased	9.4829	9.5086	0.0257
16	20	Unbiased	9.6163	9.7095	0.0932
17	20	Biased	9.5803	9.6537	0.0734
18	20	Unbiased	9.6332	9.6886	0.0554
19	20	Biased	9.6079	9.6514	0.0435
20	50	Unbiased	9.6889	9.8534	0.1645
21	0	Correlation	9.478	9.4684	-0.0096
22	50	Unbiased	9.4891	9.6605	0.1714
23	0	Correlation	9.4873	9.4733	-0.014
24	20	Biased	9.4869	9.5438	0.0569
26	50	Biased	9.5164	9.628	0.1116
27	30	Unbiased	9.4821	9.5371	0.055
28	30	Biased	9.5571	9.6602	0.1031
29	30	Unbiased	9.5496	9.6229	0.0733
30	20	Biased	9.4993	9.5726	0.0733
31	30	Unbiased	9.4216	9.4039	-0.0177
33	30	Biased	9.3843	9.4571	0.0728
34	50	Unbiased	9.6567	9.8085	0.1518
35	20	Unbiased	9.7469	9.765	0.0181
41	30	Biased	9.3337	9.5583	0.2246

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	9.3756	9.475	9.5591	0.075528	9.3896	9.4734	9.5622	0.070552	-0.014	-0.001625	0.014	0.012691
20	9.4829	9.5791	9.7469	0.084877	9.5086	9.6393	9.765	0.079733	0.0181	0.06027	0.104	0.027141
30	9.3337	9.4833	9.6146	0.095795	9.4039	9.5694	9.7263	0.1104	-0.0177	0.08605	0.2246	0.062736
50	9.4891	9.5818	9.6889	0.075982	9.6014	9.7099	9.8534	0.086775	0.1004	0.12805	0.1714	0.02709

Device Test: 14.13 IDD_DIS|STANDBY CURRENT/IN/14/14/0/0/5/500kHz//@IDD_DIS





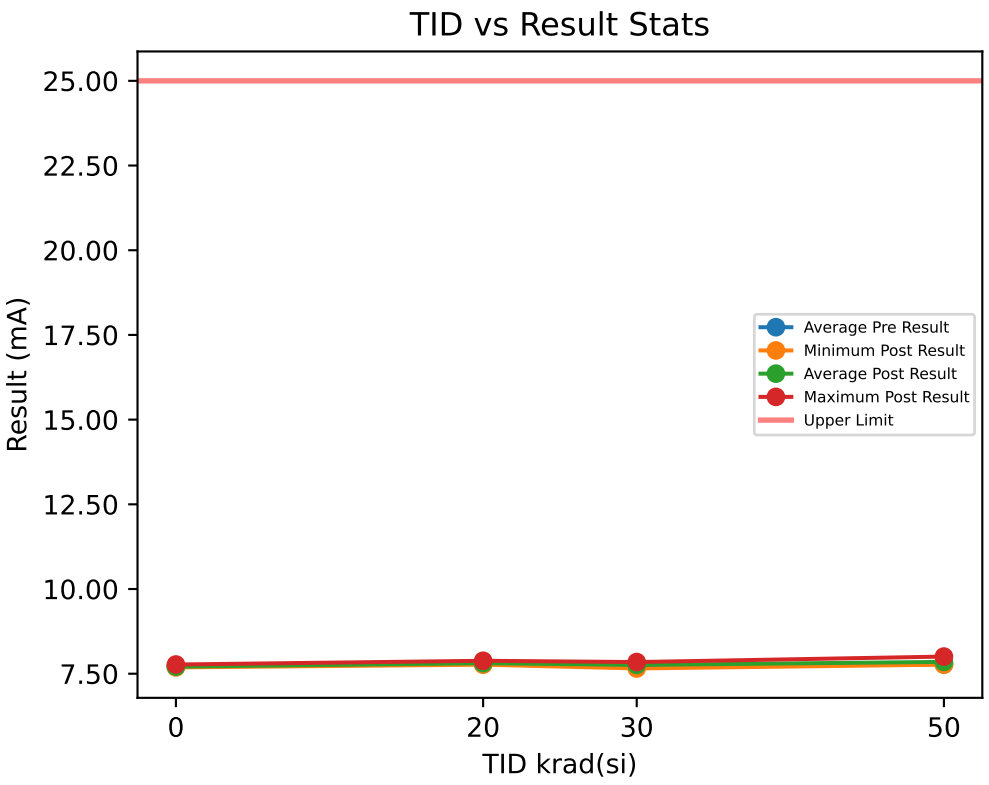
Test Results (Upper Limit = 8.0 (mA))

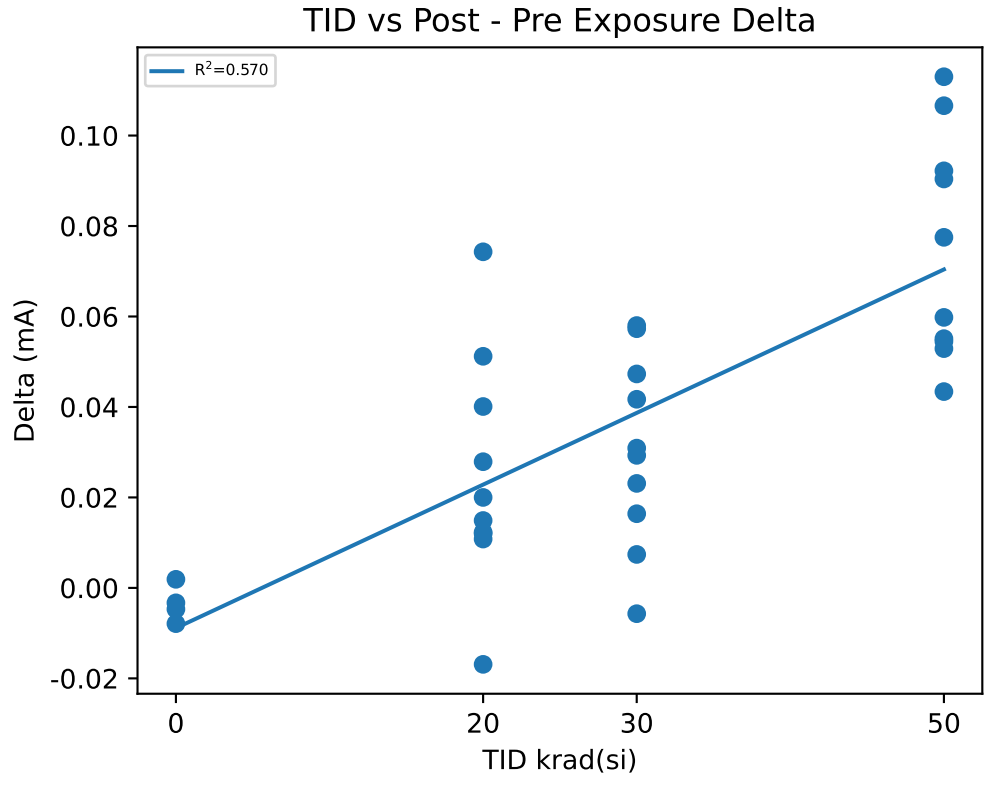
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	5.0505	5.0632	0.0127
2	20	Unbiased	5.0625	5.0521	-0.0104
3	50	Biased	4.9773	4.9811	0.0038
4	30	Unbiased	5.032	5.0638	0.0318
5	50	Unbiased	5.0963	5.1216	0.0253
6	30	Biased	5.0445	5.0525	0.008
7	50	Biased	5.1138	5.143	0.0292
8	30	Unbiased	5.1025	5.1239	0.0214
9	20	Unbiased	5.0042	5.0199	0.0157
10	50	Biased	5.0483	5.0515	0.0032
11	30	Biased	4.9526	4.9543	0.0017
12	0	Correlation	5.0082	5.0214	0.0132
13	0	Correlation	5.1187	5.1102	-0.0085
14	50	Unbiased	5.1128	5.1271	0.0143
15	20	Biased	5.0262	5.027	0.0008
16	20	Unbiased	5.1137	5.1381	0.0244
17	20	Biased	5.1058	5.1259	0.0201
18	20	Unbiased	5.0661	5.0701	0.004
19	20	Biased	5.0357	5.034	-0.0017
20	50	Unbiased	5.1544	5.1882	0.0338
21	0	Correlation	5.0929	5.0892	-0.0037
22	50	Unbiased	5.0707	5.0926	0.0219
23	0	Correlation	5.0138	5.0132	-0.0006
24	20	Biased	5.0274	5.0473	0.0199
26	50	Biased	5.0946	5.1155	0.0209
27	30	Unbiased	5.0767	5.0778	0.0011
28	30	Biased	5.0542	5.0703	0.0161
29	30	Unbiased	4.9867	4.9786	-0.0081
30	20	Biased	5.0815	5.0904	0.0089
31	30	Unbiased	5.0009	5.0008	-0.0001
33	30	Biased	5.0286	5.0403	0.0117
34	50	Unbiased	5.163	5.1877	0.0247
35	20	Unbiased	5.173	5.1695	-0.0035
41	30	Biased	5.0116	5.0284	0.0168

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.0082	5.0584	5.1187	0.055784	5.0132	5.0585	5.1102	0.048456	-0.0085	0.0001	0.0132	0.0093184
20	5.0042	5.0696	5.173	0.050818	5.0199	5.0774	5.1695	0.051659	-0.0104	0.00782	0.0244	0.011783
30	4.9526	5.029	5.1025	0.043819	4.9543	5.0391	5.1239	0.050427	-0.0081	0.01004	0.0318	0.011894
50	4.9773	5.0882	5.163	0.054735	4.9811	5.1071	5.1882	0.063375	0.0032	0.01898	0.0338	0.010273

Device Test: 14.14 IDD|SUPPLY CURRENT/IN/4.5/4.5/0/0/4.5/1MHz//@IDD_ACT_1M_NOLOAD





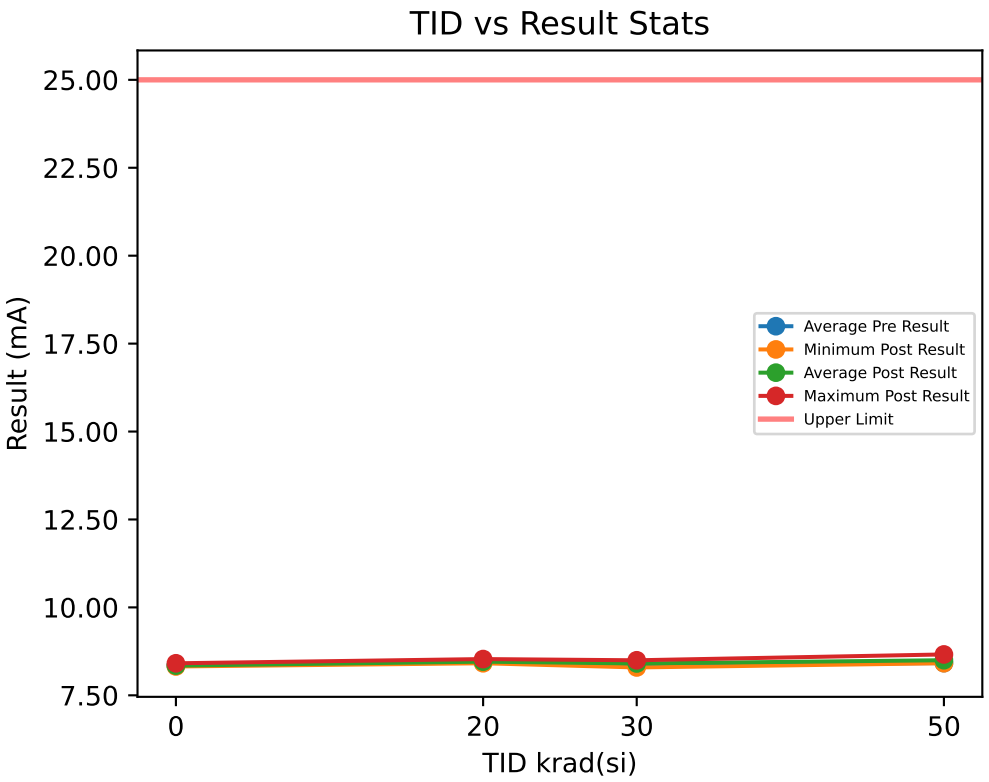
Test Results (Upper Limit = 25.0 (mA))

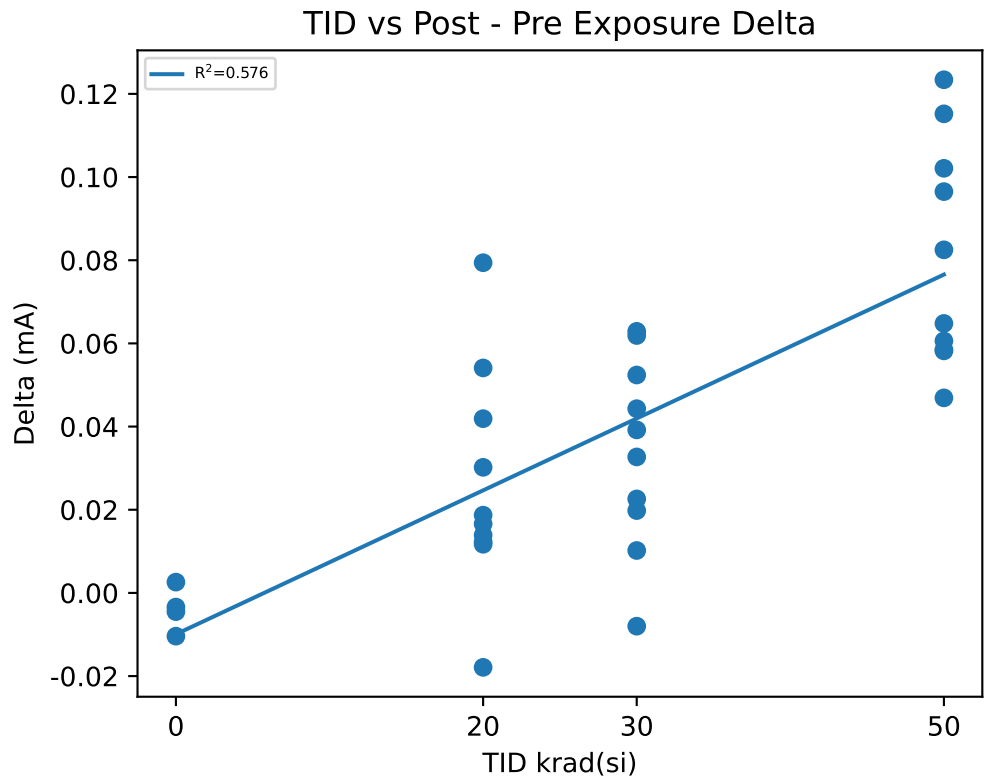
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	7.7141	7.7686	0.0545
2	20	Unbiased	7.7886	7.8006	0.012
3	50	Biased	7.7277	7.7875	0.0598
4	30	Unbiased	7.7573	7.8153	0.058
5	50	Unbiased	7.7723	7.8274	0.0551
6	30	Biased	7.6777	7.735	0.0573
7	50	Biased	7.8403	7.9307	0.0904
8	30	Unbiased	7.8054	7.8347	0.0293
9	20	Unbiased	7.7466	7.8209	0.0743
10	50	Biased	7.7304	7.8226	0.0922
11	30	Biased	7.6969	7.72	0.0231
12	0	Correlation	7.691	7.6929	0.0019
13	0	Correlation	7.7761	7.7714	-0.0047
14	50	Unbiased	7.8509	7.8943	0.0434
15	20	Biased	7.7802	7.791	0.0108
16	20	Unbiased	7.7721	7.8	0.0279
17	20	Biased	7.8417	7.8818	0.0401
18	20	Unbiased	7.8046	7.8169	0.0123
19	20	Biased	7.7746	7.7946	0.02
20	50	Unbiased	7.8993	8.0059	0.1066
21	0	Correlation	7.6953	7.6874	-0.0079
22	50	Unbiased	7.6956	7.8086	0.113
23	0	Correlation	7.6899	7.6866	-0.0033
24	20	Biased	7.7521	7.767	0.0149
26	50	Biased	7.7308	7.8083	0.0775
27	30	Unbiased	7.7899	7.7973	0.0074
28	30	Biased	7.7969	7.8442	0.0473
29	30	Unbiased	7.7431	7.7595	0.0164
30	20	Biased	7.7294	7.7806	0.0512
31	30	Unbiased	7.6881	7.6824	-0.0057
33	30	Biased	7.7113	7.753	0.0417
34	50	Unbiased	7.7843	7.8372	0.0529
35	20	Unbiased	7.8729	7.856	-0.0169
41	30	Biased	7.6244	7.6553	0.0309

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.6899	7.7131	7.7761	0.042081	7.6866	7.7096	7.7714	0.041312	-0.0079	-0.0035	0.0019	0.0040825
20	7.7294	7.7863	7.8729	0.043803	7.767	7.8109	7.8818	0.034847	-0.0169	0.02466	0.0743	0.025313
30	7.6244	7.7291	7.8054	0.059391	7.6553	7.7597	7.8442	0.063575	-0.0057	0.03057	0.058	0.021033
50	7.6956	7.7746	7.8993	0.068118	7.7686	7.8491	8.0059	0.073168	0.0434	0.07454	0.113	0.024752

Device Test: 14.15 IDD|SUPPLY CURRENT/IN/5/5/0/0/5/1MHz//@IDD_ACT_1M_NOLOAD





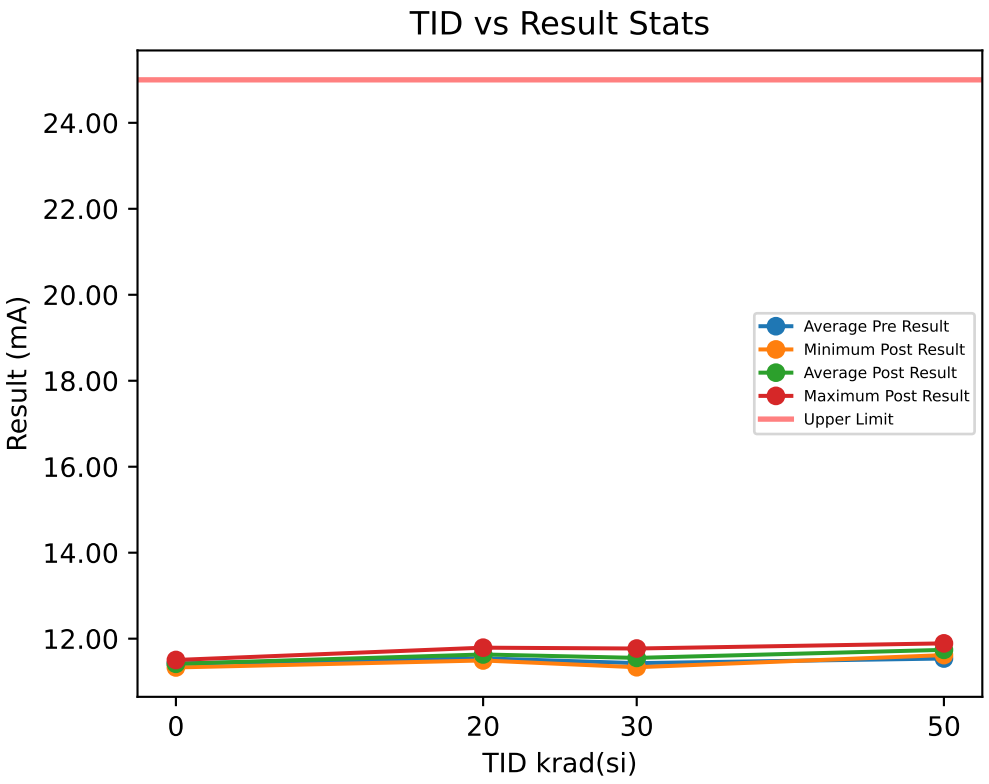
Test Results (Upper Limit = 25.0 (mA))

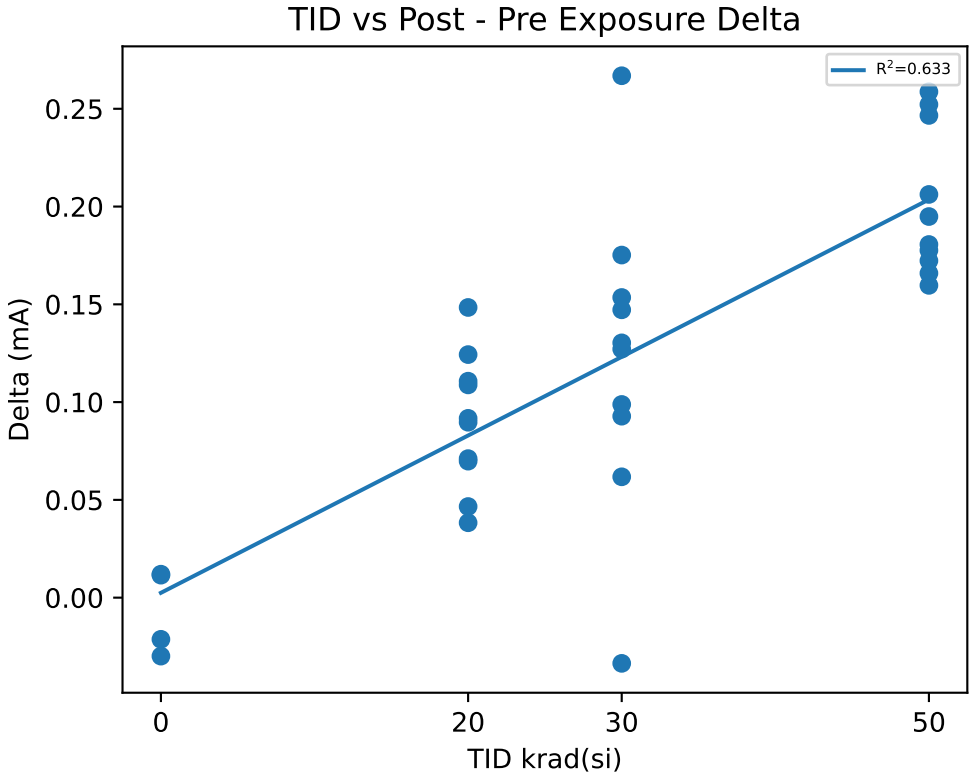
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	8.354	8.4125	0.0585
2	20	Unbiased	8.4373	8.4512	0.0139
3	50	Biased	8.376	8.4408	0.0648
4	30	Unbiased	8.4041	8.466	0.0619
5	50	Unbiased	8.4118	8.4724	0.0606
6	30	Biased	8.3154	8.3783	0.0629
7	50	Biased	8.4855	8.582	0.0965
8	30	Unbiased	8.4505	8.4832	0.0327
9	20	Unbiased	8.3918	8.4712	0.0794
10	50	Biased	8.3691	8.4712	0.1021
11	30	Biased	8.3436	8.3662	0.0226
12	0	Correlation	8.3185	8.3211	0.0026
13	0	Correlation	8.4141	8.4107	-0.0034
14	50	Unbiased	8.4999	8.5468	0.0469
15	20	Biased	8.4233	8.435	0.0117
16	20	Unbiased	8.4148	8.445	0.0302
17	20	Biased	8.489	8.5309	0.0419
18	20	Unbiased	8.4492	8.4615	0.0123
19	20	Biased	8.4229	8.4416	0.0187
20	50	Unbiased	8.5471	8.6623	0.1152
21	0	Correlation	8.3304	8.32	-0.0104
22	50	Unbiased	8.3372	8.4606	0.1234
23	0	Correlation	8.331	8.3265	-0.0045
24	20	Biased	8.3947	8.4113	0.0166
26	50	Biased	8.3693	8.4518	0.0825
27	30	Unbiased	8.4308	8.441	0.0102
28	30	Biased	8.4438	8.4962	0.0524
29	30	Unbiased	8.3914	8.4112	0.0198
30	20	Biased	8.3696	8.4237	0.0541
31	30	Unbiased	8.3328	8.3248	-0.008
33	30	Biased	8.3513	8.3956	0.0443
34	50	Unbiased	8.423	8.4812	0.0582
35	20	Unbiased	8.521	8.5031	-0.0179
41	30	Biased	8.253	8.2922	0.0392

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	8.3185	8.3485	8.4141	0.044111	8.32	8.3446	8.4107	0.044175	-0.0104	-0.003925	0.0026	0.0053263
20	8.3696	8.4314	8.521	0.045759	8.4113	8.4574	8.5309	0.036366	-0.0179	0.02609	0.0794	0.026913
30	8.253	8.3717	8.4505	0.063523	8.2922	8.4055	8.4962	0.067452	-0.008	0.0338	0.0629	0.02297
50	8.3372	8.4173	8.5471	0.070821	8.4125	8.4982	8.6623	0.07616	0.0469	0.08087	0.1234	0.026921

Device Test: 14.16 IDD|SUPPLY CURRENT/IN/12/12/0/0/5/1MHz//@IDD_ACT_1M_NOLOAD





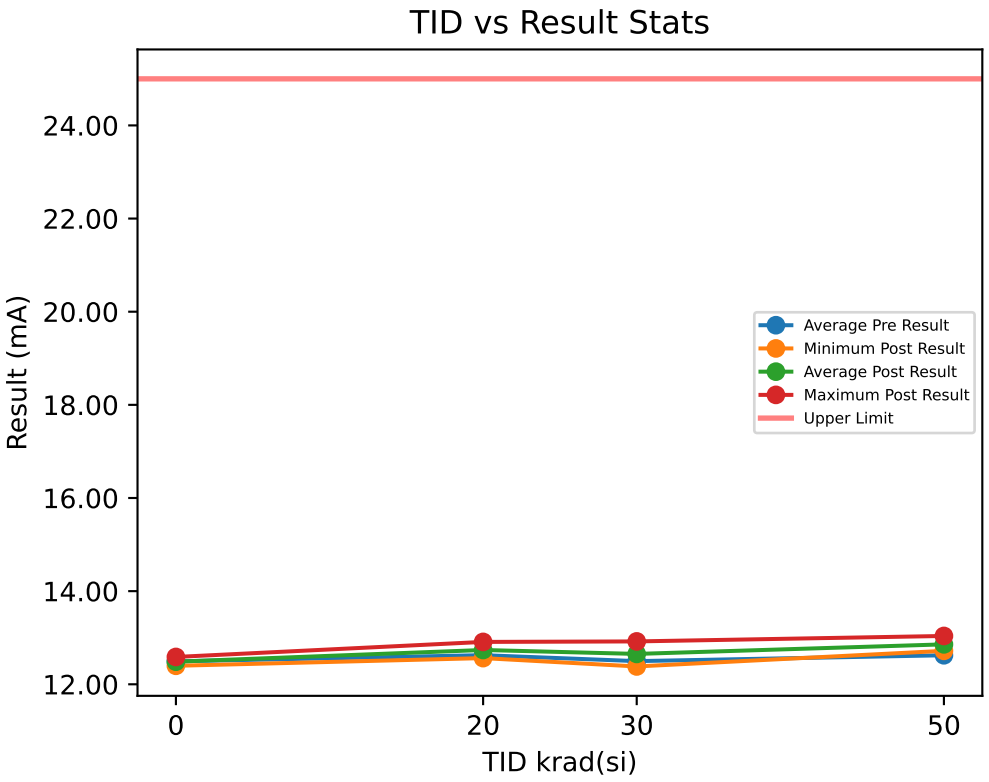
Test Results (Upper Limit = 25.0 (mA))

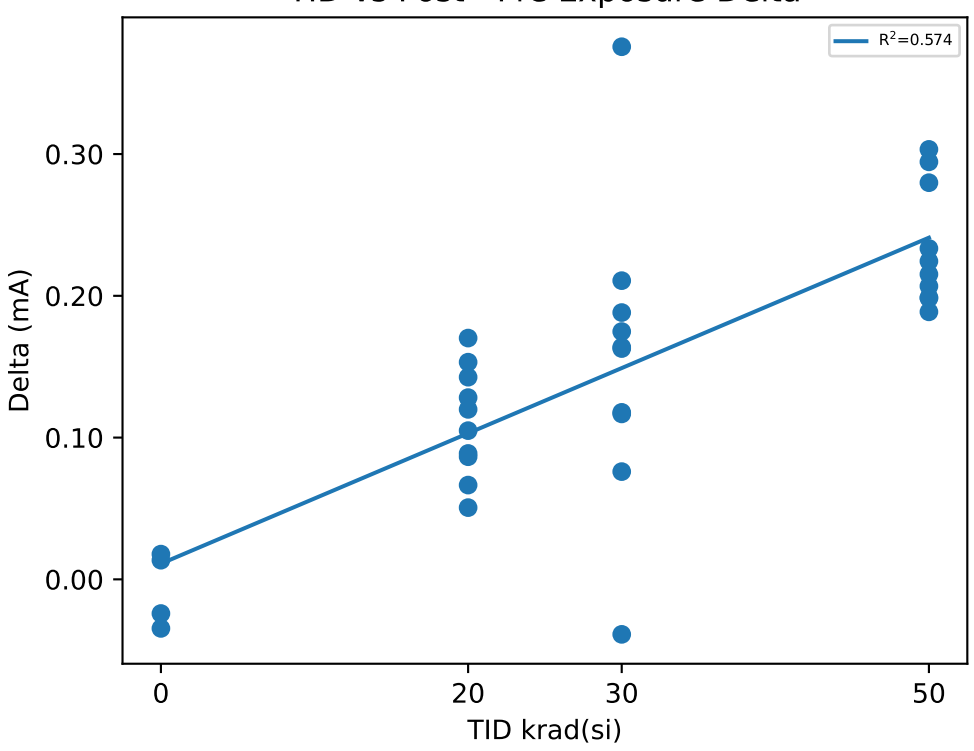
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	11.452	11.618	0.1659
2	20	Unbiased	11.632	11.743	0.1107
3	50	Biased	11.563	11.723	0.1597
4	30	Unbiased	11.596	11.771	0.1752
5	50	Unbiased	11.505	11.682	0.1776
6	30	Biased	11.412	11.559	0.1472
7	50	Biased	11.582	11.777	0.1949
8	30	Unbiased	11.565	11.692	0.1271
9	20	Unbiased	11.47	11.619	0.1484
10	50	Biased	11.511	11.717	0.2062
11	30	Biased	11.375	11.437	0.0618
12	0	Correlation	11.319	11.331	0.0115
13	0	Correlation	11.492	11.504	0.012
14	50	Unbiased	11.636	11.816	0.1806
15	20	Biased	11.455	11.493	0.0383
16	20	Unbiased	11.564	11.688	0.1243
17	20	Biased	11.521	11.611	0.0897
18	20	Unbiased	11.596	11.688	0.0917
19	20	Biased	11.607	11.677	0.0698
20	50	Unbiased	11.644	11.891	0.2466
21	0	Correlation	11.433	11.412	-0.0213
22	50	Unbiased	11.426	11.684	0.2587
23	0	Correlation	11.446	11.416	-0.0299
24	20	Biased	11.441	11.512	0.0711
26	50	Biased	11.452	11.625	0.1723
27	30	Unbiased	11.403	11.495	0.0928
28	30	Biased	11.486	11.64	0.1535
29	30	Unbiased	11.562	11.692	0.1303
30	20	Biased	11.396	11.505	0.1088
31	30	Unbiased	11.369	11.335	-0.0336
33	30	Biased	11.28	11.378	0.0988
34	50	Unbiased	11.612	11.864	0.2522
35	20	Unbiased	11.744	11.791	0.0466
41	30	Biased	11.265	11.532	0.2669

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	11.319	11.423	11.492	0.07366	11.331	11.416	11.504	0.07105	-0.0299	-0.006925	0.012	0.021849
20	11.396	11.543	11.744	0.10613	11.493	11.633	11.791	0.10348	0.0383	0.08994	0.1484	0.03447
30	11.265	11.431	11.596	0.11732	11.335	11.553	11.771	0.14486	-0.0336	0.122	0.2669	0.078013
50	11.426	11.538	11.644	0.080326	11.618	11.74	11.891	0.094775	0.1597	0.20147	0.2587	0.037738

Device Test: 14.17 IDD|SUPPLY CURRENT/IN/14/14/0/0/5/1MHz//@IDD_ACT_1M_NOLOAD





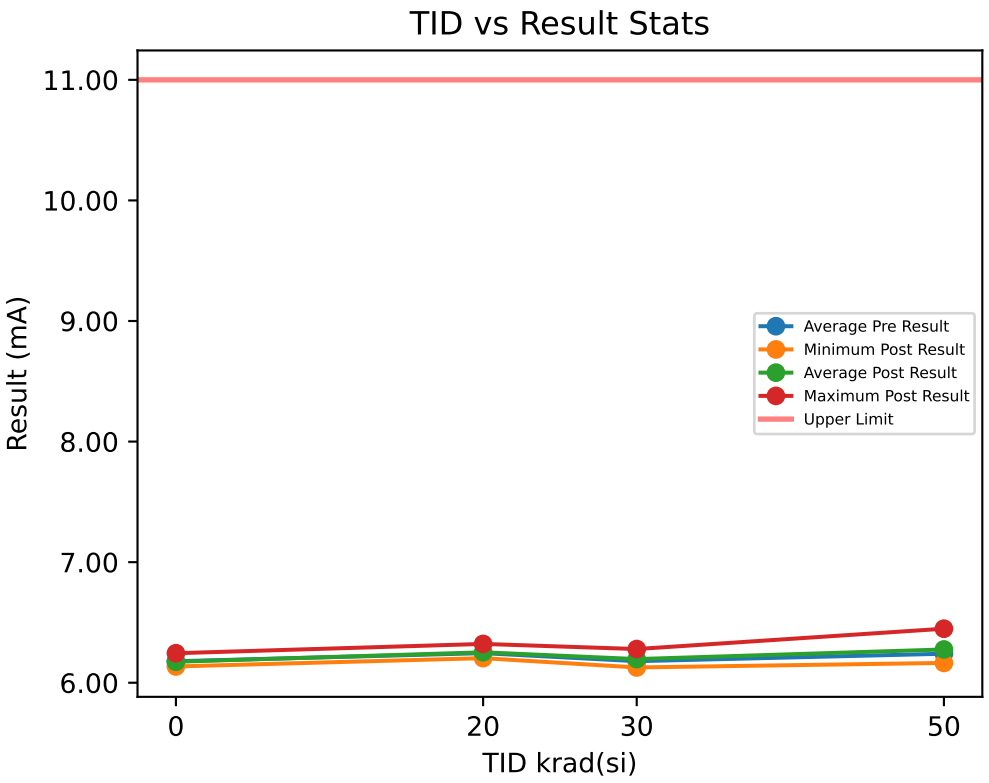
Test Results (Upper Limit = 25.0 (mA))

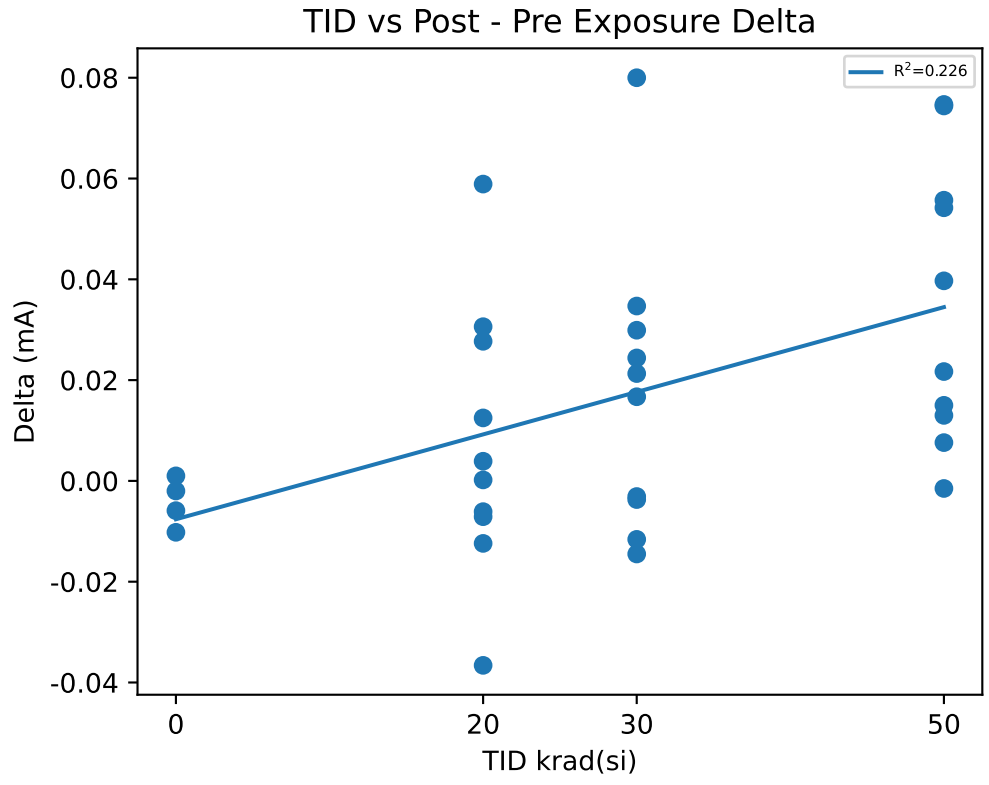
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	12.527	12.726	0.1988
2	20	Unbiased	12.727	12.87	0.1426
3	50	Biased	12.655	12.844	0.1887
4	30	Unbiased	12.71	12.921	0.2107
5	50	Unbiased	12.571	12.778	0.2068
6	30	Biased	12.488	12.662	0.1748
7	50	Biased	12.652	12.876	0.2244
8	30	Unbiased	12.656	12.818	0.1628
9	20	Unbiased	12.553	12.723	0.1702
10	50	Biased	12.634	12.867	0.2334
11	30	Biased	12.425	12.501	0.076
12	0	Correlation	12.384	12.397	0.0135
13	0	Correlation	12.569	12.587	0.0178
14	50	Unbiased	12.742	12.957	0.2152
15	20	Biased	12.512	12.562	0.0506
16	20	Unbiased	12.671	12.824	0.1532
17	20	Biased	12.586	12.691	0.1049
18	20	Unbiased	12.691	12.811	0.1199
19	20	Biased	12.718	12.805	0.0865
20	50	Unbiased	12.717	12.997	0.2798
21	0	Correlation	12.49	12.466	-0.0241
22	50	Unbiased	12.479	12.774	0.2945
23	0	Correlation	12.527	12.493	-0.0346
24	20	Biased	12.498	12.587	0.0888
26	50	Biased	12.52	12.718	0.1984
27	30	Unbiased	12.44	12.557	0.1167
28	30	Biased	12.536	12.724	0.1882
29	30	Unbiased	12.677	12.841	0.1638
30	20	Biased	12.452	12.581	0.1282
31	30	Unbiased	12.422	12.383	-0.0388
33	30	Biased	12.309	12.426	0.1178
34	50	Unbiased	12.734	13.038	0.3033
35	20	Unbiased	12.843	12.91	0.0665
41	30	Biased	12.311	12.687	0.3757

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	12.384	12.492	12.569	0.0793	12.397	12.486	12.587	0.078475	-0.0346	-0.00685	0.0178	0.02639
20	12.452	12.625	12.843	0.12413	12.562	12.736	12.91	0.12693	0.0506	0.11114	0.1702	0.038611
30	12.309	12.497	12.71	0.14481	12.383	12.652	12.921	0.18169	-0.0388	0.15477	0.3757	0.10546
50	12.479	12.623	12.742	0.094678	12.718	12.857	13.038	0.11189	0.1887	0.23433	0.3033	0.042562

Device Test: 14.2 IDD|SUPPLY CURRENT/IN/5/5/0/0/5/100kHz//@IDD_ACT_100K_NOLOAD





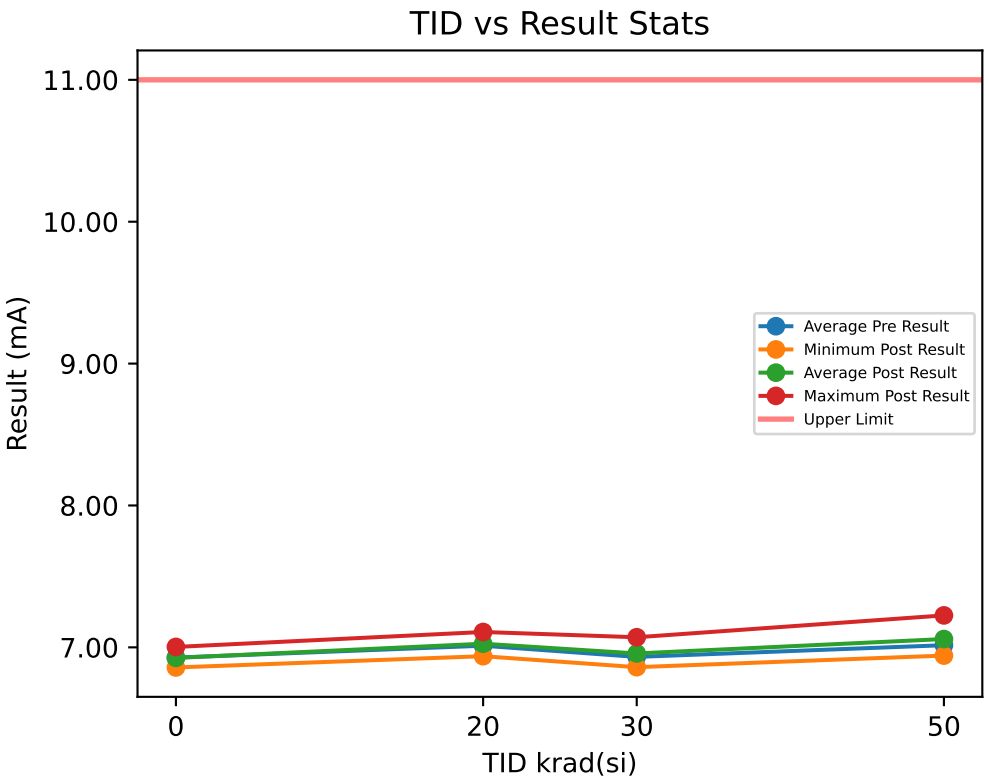
Test Results (Upper Limit = 11.0 (mA))

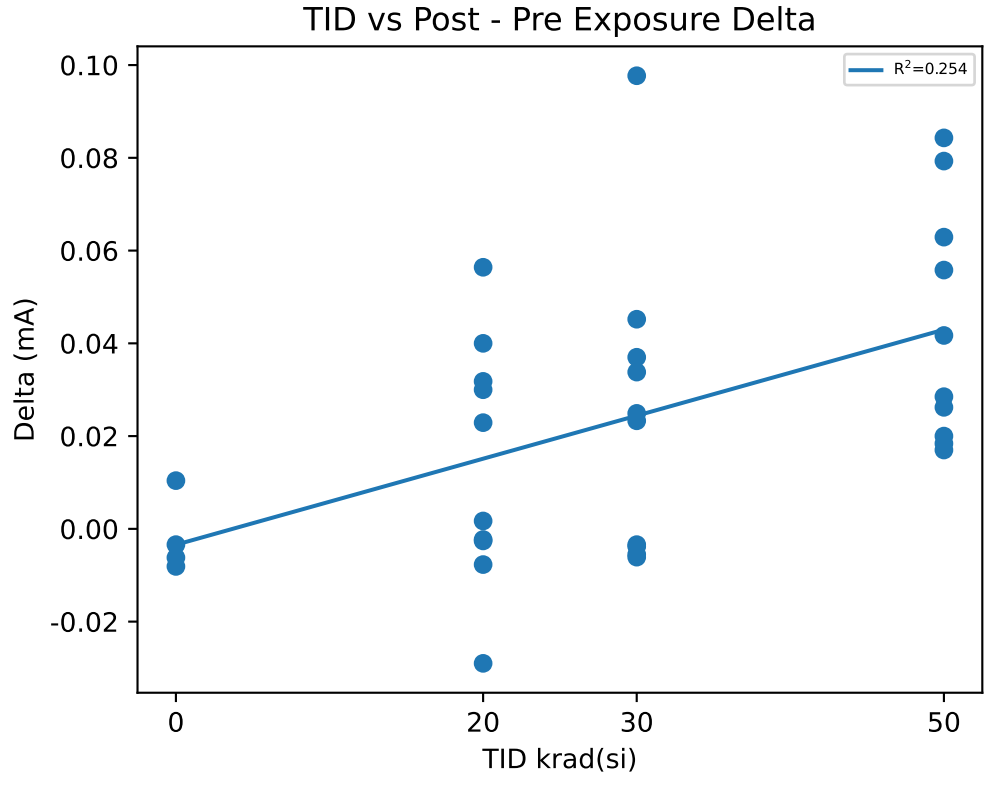
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	6.1778	6.1908	0.013
2	20	Unbiased	6.2199	6.2075	-0.0124
3	50	Biased	6.1494	6.1644	0.015
4	30	Unbiased	6.1891	6.2238	0.0347
5	50	Unbiased	6.2483	6.27	0.0217
6	30	Biased	6.1471	6.177	0.0299
7	50	Biased	6.3087	6.3629	0.0542
8	30	Unbiased	6.2628	6.2795	0.0167
9	20	Unbiased	6.2187	6.2776	0.0589
10	50	Biased	6.2022	6.2579	0.0557
11	30	Biased	6.1307	6.1276	-0.0031
12	0	Correlation	6.1688	6.1698	0.001
13	0	Correlation	6.255	6.2448	-0.0102
14	50	Unbiased	6.3208	6.3284	0.0076
15	20	Biased	6.2341	6.228	-0.0061
16	20	Unbiased	6.2536	6.2661	0.0125
17	20	Biased	6.2943	6.322	0.0277
18	20	Unbiased	6.2711	6.264	-0.0071
19	20	Biased	6.221	6.2212	0.0002
20	50	Unbiased	6.3734	6.4481	0.0747
21	0	Correlation	6.141	6.1351	-0.0059
22	50	Unbiased	6.1741	6.2485	0.0744
23	0	Correlation	6.1487	6.1467	-0.002
24	20	Biased	6.2001	6.204	0.0039
26	50	Biased	6.1945	6.2342	0.0397
27	30	Unbiased	6.2677	6.2532	-0.0145
28	30	Biased	6.2569	6.2782	0.0213
29	30	Unbiased	6.1488	6.1372	-0.0116
30	20	Biased	6.2224	6.253	0.0306
31	30	Unbiased	6.1305	6.1268	-0.0037
33	30	Biased	6.1883	6.2127	0.0244
34	50	Unbiased	6.2562	6.2547	-0.0015
35	20	Unbiased	6.3189	6.2823	-0.0366
41	30	Biased	6.0664	6.1464	0.08

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.141	6.1784	6.255	0.05241	6.1351	6.1741	6.2448	0.049291	-0.0102	-0.004275	0.001	0.0048562
20	6.2001	6.2454	6.3189	0.03828	6.204	6.2526	6.322	0.037451	-0.0366	0.00716	0.0589	0.026693
30	6.0664	6.1788	6.2677	0.067033	6.1268	6.1962	6.2795	0.061281	-0.0145	0.01741	0.08	0.028212
50	6.1494	6.2405	6.3734	0.074006	6.1644	6.276	6.4481	0.083633	-0.0015	0.03545	0.0747	0.028066

Device Test: 14.3 IDD|SUPPLY CURRENT/IN/12/12/0/0/5/100kHz//@IDD_ACT_100K_NOLOAD





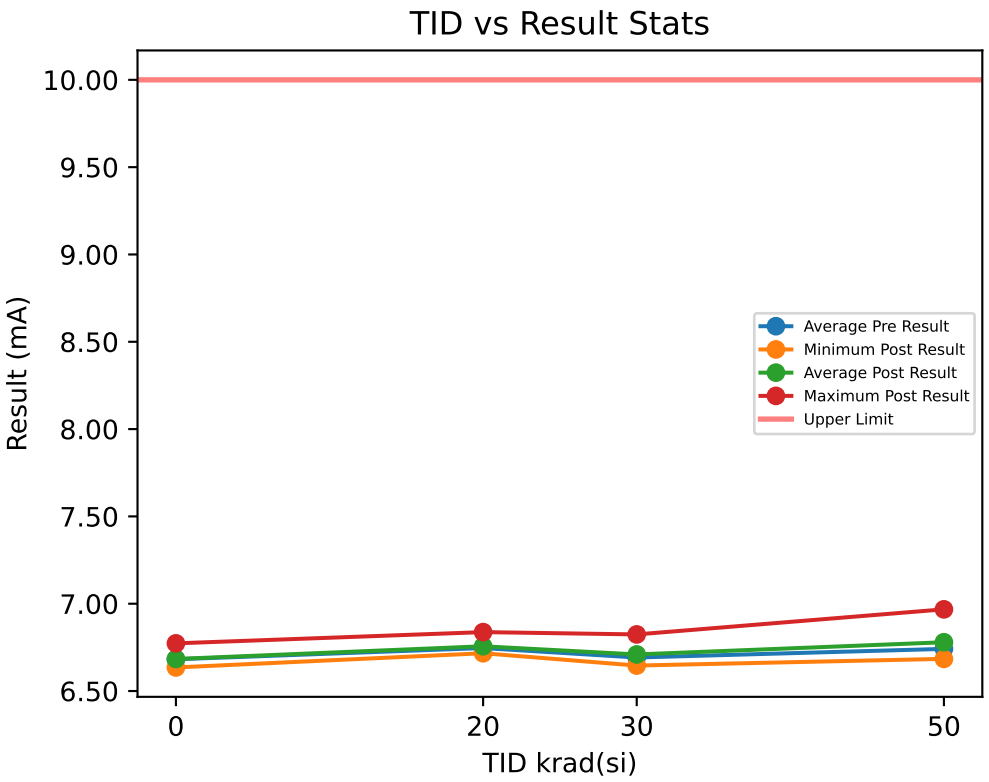
Test Results (Upper Limit = 11.0 (mA))

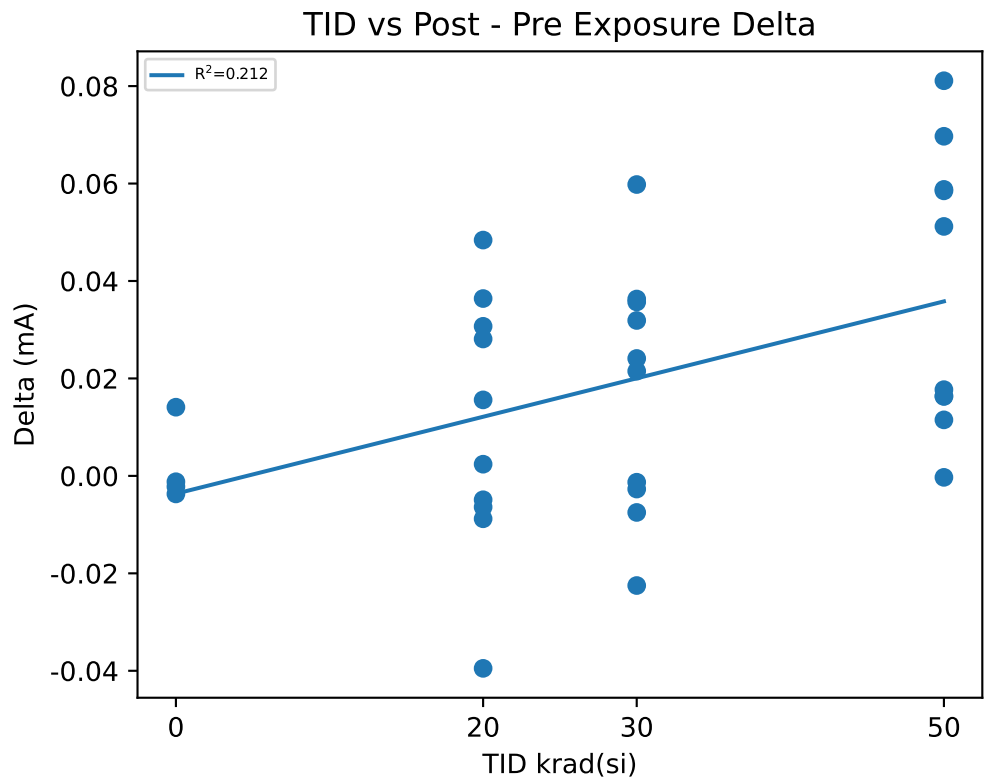
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	6.9565	6.9765	0.02
2	20	Unbiased	7.0218	7.0141	-0.0077
3	50	Biased	6.9236	6.942	0.0184
4	30	Unbiased	6.9692	7.0144	0.0452
5	50	Unbiased	7.0046	7.0331	0.0285
6	30	Biased	6.9158	6.9496	0.0338
7	50	Biased	7.0728	7.1357	0.0629
8	30	Unbiased	7.0479	7.0712	0.0233
9	20	Unbiased	6.9553	7.0117	0.0564
10	50	Biased	6.9573	7.0131	0.0558
11	30	Biased	6.8641	6.8603	-0.0038
12	0	Correlation	6.8479	6.8583	0.0104
13	0	Correlation	7.011	7.0029	-0.0081
14	50	Unbiased	7.0902	7.1072	0.017
15	20	Biased	6.9403	6.9377	-0.0026
16	20	Unbiased	7.0402	7.0702	0.03
17	20	Biased	7.0356	7.0756	0.04
18	20	Unbiased	7.0472	7.0449	-0.0023
19	20	Biased	6.9878	6.9895	0.0017
20	50	Unbiased	7.1409	7.2252	0.0843
21	0	Correlation	6.9326	6.9264	-0.0062
22	50	Unbiased	6.9692	7.0485	0.0793
23	0	Correlation	6.9191	6.9157	-0.0034
24	20	Biased	6.9477	6.9706	0.0229
26	50	Biased	6.9784	7.0201	0.0417
27	30	Unbiased	6.9944	6.991	-0.0034
28	30	Biased	7.0288	7.0658	0.037
29	30	Unbiased	6.8983	6.8928	-0.0055
30	20	Biased	7.0013	7.0331	0.0318
31	30	Unbiased	6.8843	6.8782	-0.0061
33	30	Biased	6.9118	6.9367	0.0249
34	50	Unbiased	7.0576	7.0838	0.0262
35	20	Unbiased	7.1373	7.1083	-0.029
41	30	Biased	6.8121	6.9098	0.0977

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.8479	6.9276	7.011	0.066845	6.8583	6.9258	7.0029	0.05945	-0.0081	-0.001825	0.0104	0.0083755
20	6.9403	7.0114	7.1373	0.059231	6.9377	7.0256	7.1083	0.051787	-0.029	0.01412	0.0564	0.026115
30	6.8121	6.9327	7.0479	0.075383	6.8603	6.957	7.0712	0.075797	-0.0061	0.02431	0.0977	0.032397
50	6.9236	7.0151	7.1409	0.070956	6.942	7.0585	7.2252	0.082555	0.017	0.04341	0.0843	0.025573

Device Test: 14.30 IDD|SUPPLY CURRENT/IN/5/12/0/1000/5/100kHz//@IDD_ACT_100K_LOAD_LDO





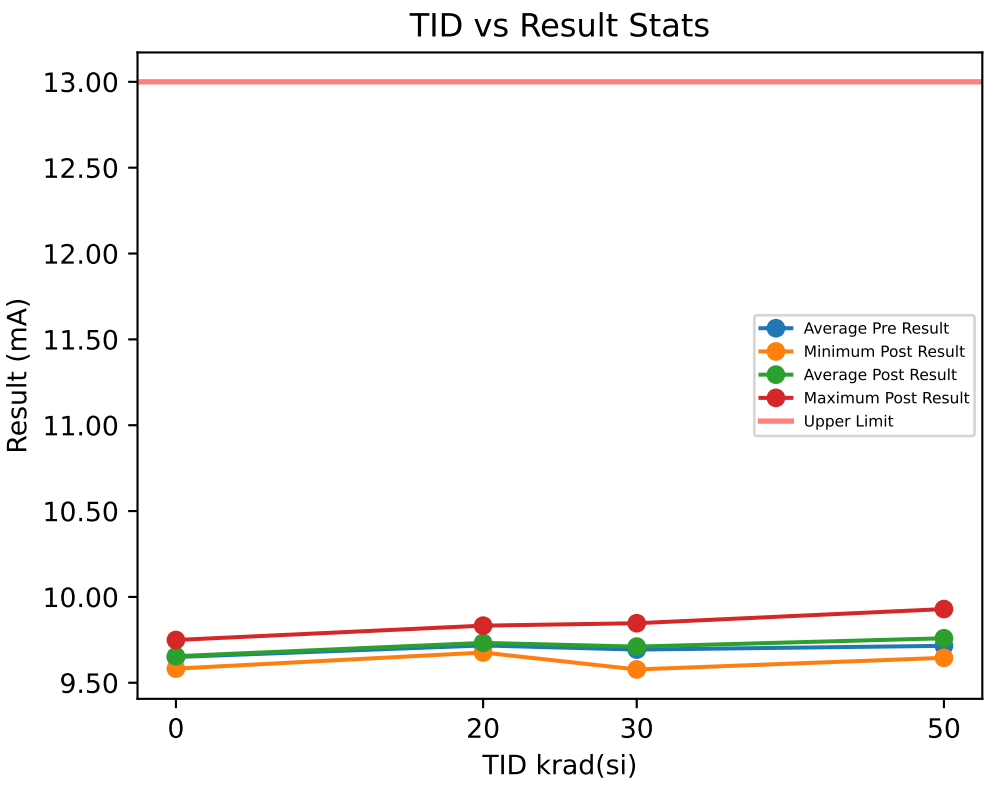
Test Results (Upper Limit = 10.0 (mA))

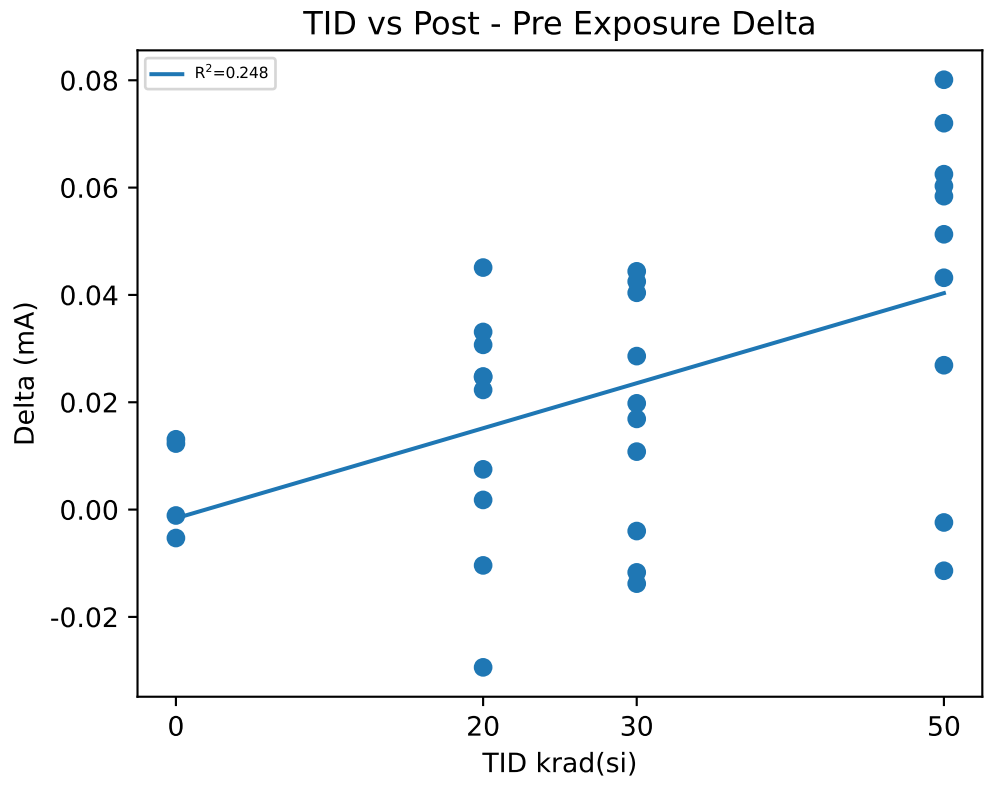
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	6.6729	6.6893	0.0164
2	20	Unbiased	6.7228	6.7164	-0.0064
3	50	Biased	6.6665	6.6842	0.0177
4	30	Unbiased	6.6899	6.7256	0.0357
5	50	Unbiased	6.7218	6.7381	0.0163
6	30	Biased	6.6476	6.6795	0.0319
7	50	Biased	6.8203	6.8791	0.0588
8	30	Unbiased	6.7588	6.7803	0.0215
9	20	Unbiased	6.7064	6.7548	0.0484
10	50	Biased	6.7049	6.7634	0.0585
11	30	Biased	6.6474	6.6461	-0.0013
12	0	Correlation	6.6434	6.6575	0.0141
13	0	Correlation	6.7767	6.773	-0.0037
14	50	Unbiased	6.8296	6.8293	-0.0003
15	20	Biased	6.7251	6.7202	-0.0049
16	20	Unbiased	6.7479	6.776	0.0281
17	20	Biased	6.8067	6.8374	0.0307
18	20	Unbiased	6.7689	6.7601	-0.0088
19	20	Biased	6.7262	6.7286	0.0024
20	50	Unbiased	6.8867	6.9678	0.0811
21	0	Correlation	6.6372	6.635	-0.0022
22	50	Unbiased	6.6706	6.7403	0.0697
23	0	Correlation	6.67	6.6688	-0.0012
24	20	Biased	6.7108	6.7264	0.0156
26	50	Biased	6.6909	6.7421	0.0512
27	30	Unbiased	6.7639	6.7414	-0.0225
28	30	Biased	6.7879	6.8242	0.0363
29	30	Unbiased	6.6767	6.6692	-0.0075
30	20	Biased	6.7188	6.7552	0.0364
31	30	Unbiased	6.6488	6.6461	-0.0027
33	30	Biased	6.7128	6.7369	0.0241
34	50	Unbiased	6.7486	6.7601	0.0115
35	20	Unbiased	6.8279	6.7884	-0.0395
41	30	Biased	6.5861	6.6459	0.0598

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.6372	6.6818	6.7767	0.06483	6.635	6.6836	6.773	0.06125	-0.0037	0.00175	0.0141	0.0082972
20	6.7064	6.7462	6.8279	0.041944	6.7164	6.7564	6.8374	0.037372	-0.0395	0.0102	0.0484	0.026481
30	6.5861	6.692	6.7879	0.063719	6.6459	6.7095	6.8242	0.062187	-0.0225	0.01753	0.0598	0.025226
50	6.6665	6.7413	6.8867	0.077996	6.6842	6.7794	6.9678	0.088418	-0.0003	0.03809	0.0811	0.02869

Device Test: 14.31 IDD|SUPPLY CURRENT/IN/5/12/0/1000/5/500kHz//@IDD_ACT_500K_LOAD_LDO





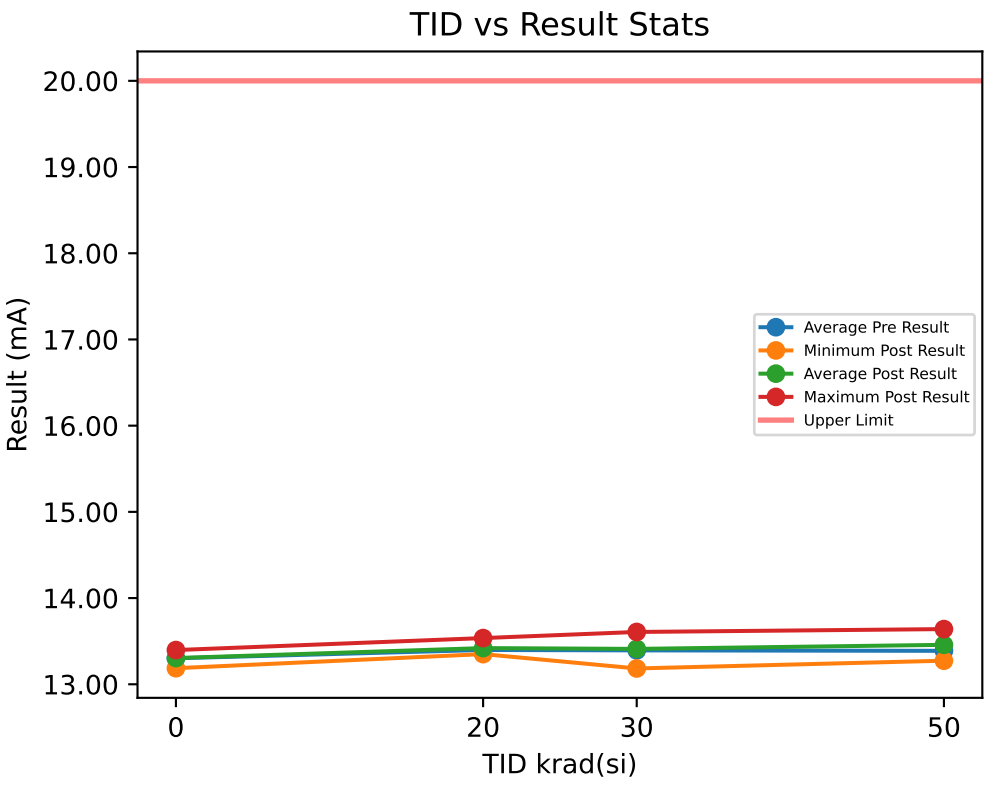
Test Results (Upper Limit = 13.0 (mA))

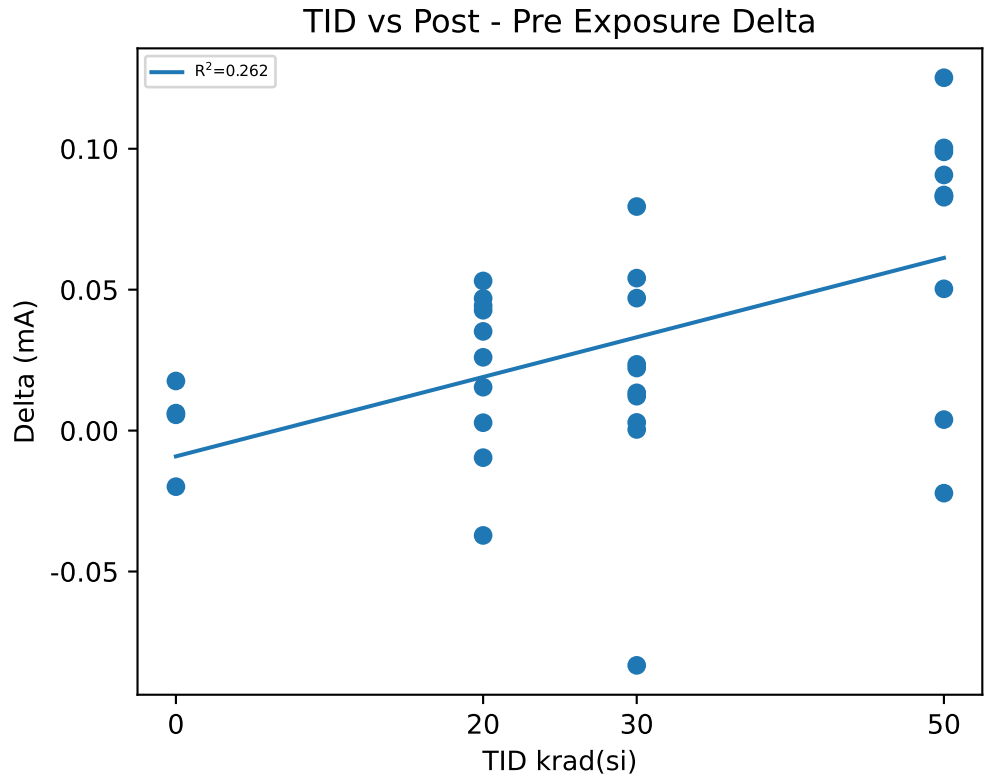
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	9.6383	9.6652	0.0269
2	20	Unbiased	9.7091	9.7109	0.0018
3	50	Biased	9.6738	9.7251	0.0513
4	30	Unbiased	9.7108	9.7512	0.0404
5	50	Unbiased	9.6567	9.6453	-0.0114
6	30	Biased	9.6314	9.6739	0.0425
7	50	Biased	9.7893	9.8694	0.0801
8	30	Unbiased	9.7367	9.7653	0.0286
9	20	Unbiased	9.6624	9.6955	0.0331
10	50	Biased	9.7008	9.7633	0.0625
11	30	Biased	9.6501	9.667	0.0169
12	0	Correlation	9.5692	9.5823	0.0131
13	0	Correlation	9.7502	9.7491	-0.0011
14	50	Unbiased	9.8239	9.8215	-0.0024
15	20	Biased	9.6686	9.6761	0.0075
16	20	Unbiased	9.7049	9.75	0.0451
17	20	Biased	9.8104	9.8327	0.0223
18	20	Unbiased	9.7312	9.7208	-0.0104
19	20	Biased	9.7145	9.7392	0.0247
20	50	Unbiased	9.8572	9.9292	0.072
21	0	Correlation	9.6298	9.6245	-0.0053
22	50	Unbiased	9.6336	9.6939	0.0603
23	0	Correlation	9.6506	9.6629	0.0123
24	20	Biased	9.7076	9.7324	0.0248
26	50	Biased	9.6622	9.7206	0.0584
27	30	Unbiased	9.7147	9.703	-0.0117
28	30	Biased	9.8024	9.8468	0.0444
29	30	Unbiased	9.724	9.72	-0.004
30	20	Biased	9.6594	9.6901	0.0307
31	30	Unbiased	9.6483	9.6591	0.0108
33	30	Biased	9.722	9.7418	0.0198
34	50	Unbiased	9.715	9.7582	0.0432
35	20	Unbiased	9.8049	9.7755	-0.0294
41	30	Biased	9.5913	9.5775	-0.0138

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	9.5692	9.65	9.7502	0.075226	9.5823	9.6547	9.7491	0.071022	-0.0053	0.00475	0.0131	0.0093443
20	9.6594	9.7173	9.8104	0.053329	9.6761	9.7323	9.8327	0.046177	-0.0294	0.01502	0.0451	0.022535
30	9.5913	9.6932	9.8024	0.061863	9.5775	9.7106	9.8468	0.072973	-0.0138	0.01739	0.0444	0.021963
50	9.6336	9.7151	9.8572	0.080412	9.6453	9.7592	9.9292	0.090474	-0.0114	0.04409	0.0801	0.030679

Device Test: 14.32 IDD|SUPPLY CURRENT/IN/5/12/0/1000/5/1MHz//@IDD_ACT_1M_LOAD_LDO





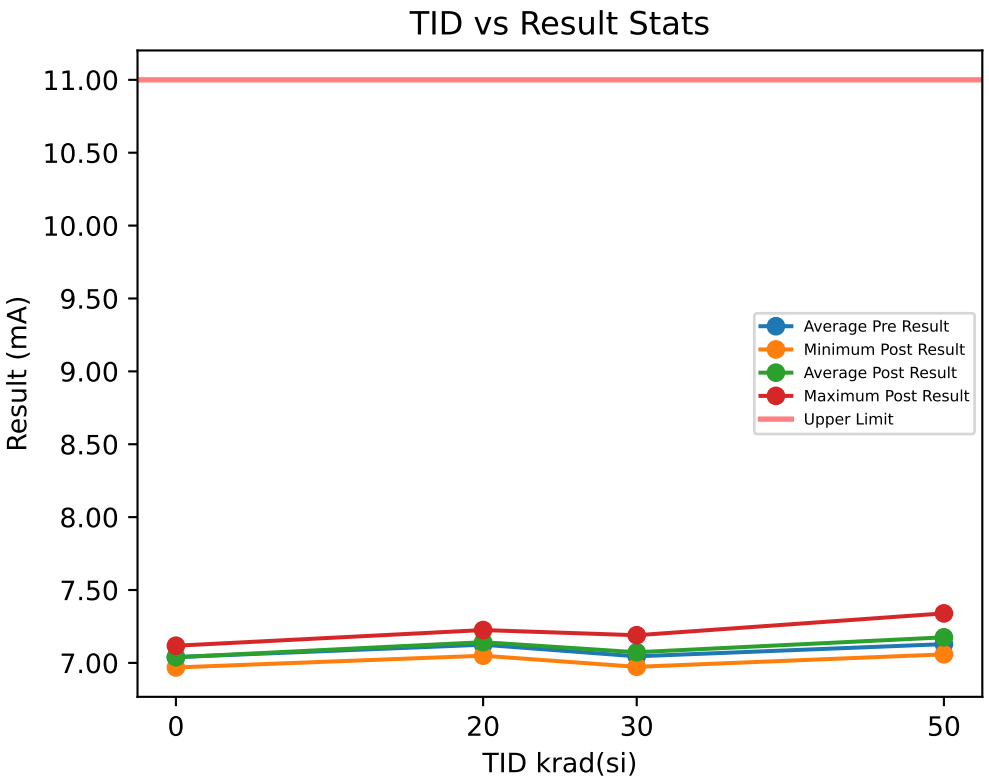
Test Results (Upper Limit = 20.0 (mA))

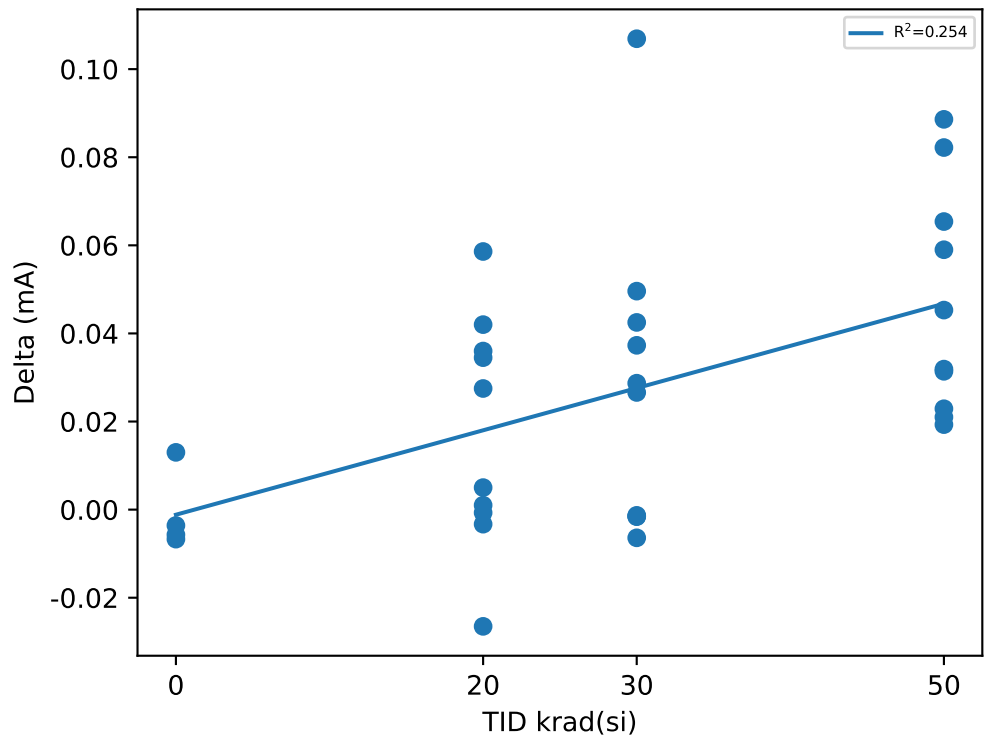
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	13.304	13.354	0.0503
2	20	Unbiased	13.417	13.432	0.0154
3	50	Biased	13.383	13.466	0.0831
4	30	Unbiased	13.419	13.466	0.047
5	50	Unbiased	13.296	13.274	-0.0222
6	30	Biased	13.292	13.346	0.0541
7	50	Biased	13.468	13.594	0.1252
8	30	Unbiased	13.409	13.431	0.0222
9	20	Unbiased	13.344	13.386	0.0427
10	50	Biased	13.363	13.445	0.0828
11	30	Biased	13.368	13.391	0.0235
12	0	Correlation	13.181	13.187	0.0056
13	0	Correlation	13.391	13.397	0.0062
14	50	Unbiased	13.537	13.541	0.0039
15	20	Biased	13.347	13.35	0.0028
16	20	Unbiased	13.349	13.402	0.0531
17	20	Biased	13.51	13.536	0.026
18	20	Unbiased	13.383	13.373	-0.0096
19	20	Biased	13.423	13.47	0.0469
20	50	Unbiased	13.54	13.64	0.1003
21	0	Correlation	13.311	13.291	-0.0199
22	50	Unbiased	13.296	13.387	0.0907
23	0	Correlation	13.325	13.342	0.0176
24	20	Biased	13.414	13.449	0.0352
26	50	Biased	13.325	13.424	0.0989
27	30	Unbiased	13.37	13.37	0.0004
28	30	Biased	13.527	13.607	0.0795
29	30	Unbiased	13.496	13.499	0.0029
30	20	Biased	13.306	13.35	0.0443
31	30	Unbiased	13.359	13.371	0.0122
33	30	Biased	13.426	13.44	0.0134
34	50	Unbiased	13.367	13.451	0.0836
35	20	Unbiased	13.486	13.449	-0.0372
41	30	Biased	13.267	13.184	-0.0833

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	13.181	13.302	13.391	0.087774	13.187	13.304	13.397	0.089564	-0.0199	0.002375	0.0176	0.015843
20	13.306	13.398	13.51	0.065127	13.35	13.42	13.536	0.058885	-0.0372	0.02196	0.0531	0.029095
30	13.267	13.393	13.527	0.081093	13.184	13.41	13.607	0.11053	-0.0833	0.01719	0.0795	0.043233
50	13.296	13.388	13.54	0.09477	13.274	13.457	13.64	0.11042	-0.0222	0.06966	0.1252	0.045954

Device Test: 14.4 IDD|SUPPLY CURRENT/IN/14/14/0/0/5/100kHz//@IDD_ACT_100K_NOLOAD





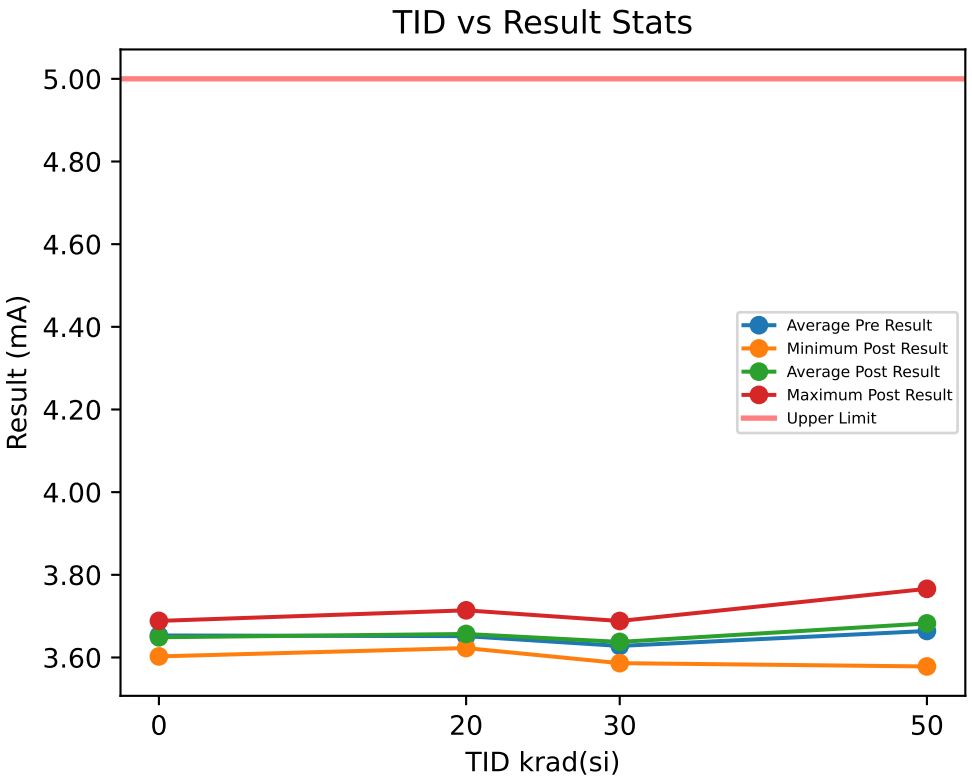
Test Results (Upper Limit = 11.0 (mA))

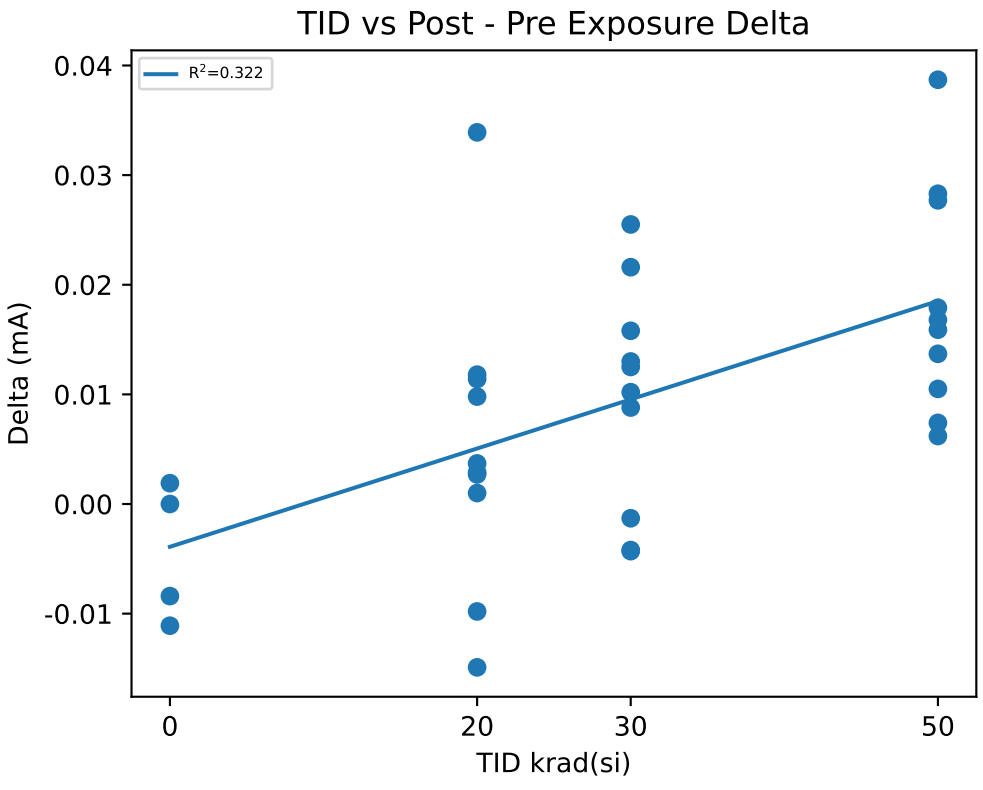
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	7.0696	7.0925	0.0229
2	20	Unbiased	7.1352	7.1319	-0.0033
3	50	Biased	7.0375	7.0585	0.021
4	30	Unbiased	7.0859	7.1355	0.0496
5	50	Unbiased	7.1163	7.1477	0.0314
6	30	Biased	7.0296	7.0669	0.0373
7	50	Biased	7.185	7.2504	0.0654
8	30	Unbiased	7.1611	7.1898	0.0287
9	20	Unbiased	7.0672	7.1258	0.0586
10	50	Biased	7.0753	7.1343	0.059
11	30	Biased	6.9745	6.973	-0.0015
12	0	Correlation	6.9557	6.9687	0.013
13	0	Correlation	7.1244	7.1177	-0.0067
14	50	Unbiased	7.2077	7.227	0.0193
15	20	Biased	7.05	7.0493	-0.0007
16	20	Unbiased	7.1541	7.1901	0.036
17	20	Biased	7.1507	7.1927	0.042
18	20	Unbiased	7.1622	7.1632	0.001
19	20	Biased	7.1044	7.1094	0.005
20	50	Unbiased	7.2511	7.3397	0.0886
21	0	Correlation	7.0447	7.039	-0.0057
22	50	Unbiased	7.0773	7.1595	0.0822
23	0	Correlation	7.0335	7.0299	-0.0036
24	20	Biased	7.0573	7.0848	0.0275
26	50	Biased	7.0915	7.1368	0.0453
27	30	Unbiased	7.1021	7.1005	-0.0016
28	30	Biased	7.1394	7.1819	0.0425
29	30	Unbiased	7.0176	7.0163	-0.0013
30	20	Biased	7.1142	7.1487	0.0345
31	30	Unbiased	6.9957	6.9893	-0.0064
33	30	Biased	7.0195	7.0461	0.0266
34	50	Unbiased	7.1752	7.2071	0.0319
35	20	Unbiased	7.2518	7.2253	-0.0265
41	30	Biased	6.925	7.0319	0.1069

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.9557	7.0396	7.1244	0.069025	6.9687	7.0388	7.1177	0.061151	-0.0067	-0.00075	0.013	0.0092572
20	7.05	7.1247	7.2518	0.060702	7.0493	7.1421	7.2253	0.053343	-0.0265	0.01741	0.0586	0.026139
30	6.925	7.045	7.1611	0.075102	6.973	7.0731	7.1898	0.076619	-0.0064	0.02808	0.1069	0.034608
50	7.0375	7.1287	7.2511	0.071021	7.0585	7.1753	7.3397	0.082344	0.0193	0.0467	0.0886	0.025711

Device Test: 14.5 ISTART|STARTUP CURRENT/IN/3.5/3.5/0/0/4.5/500kHz//@I_START





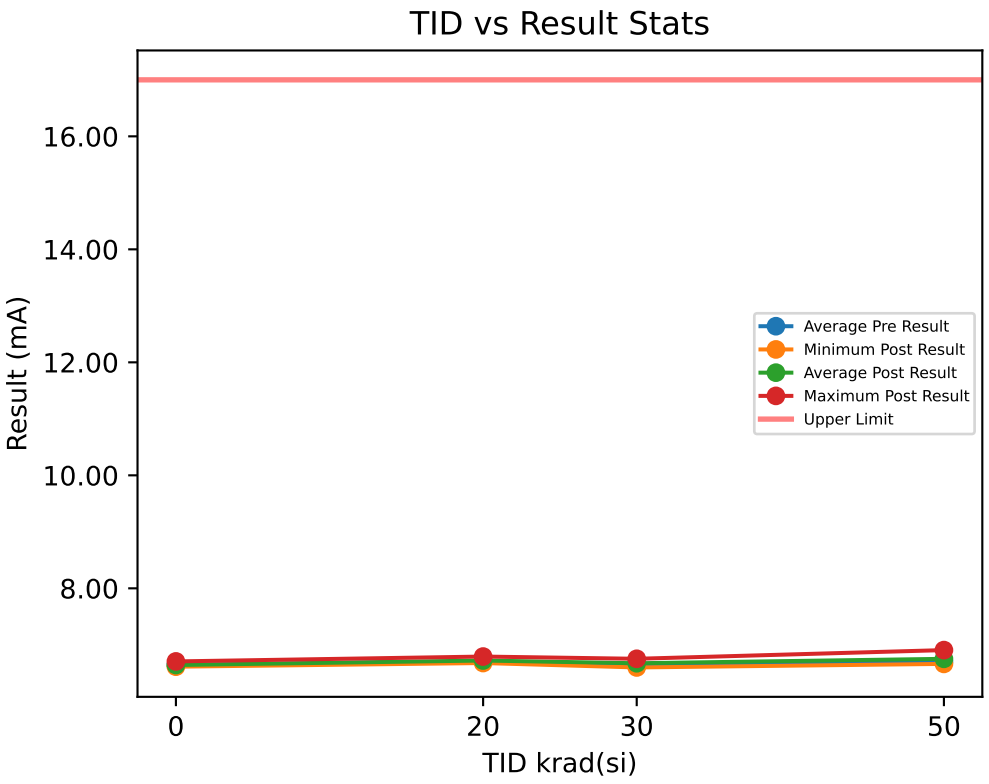
Test Results (Upper Limit = 5.0 (mA))

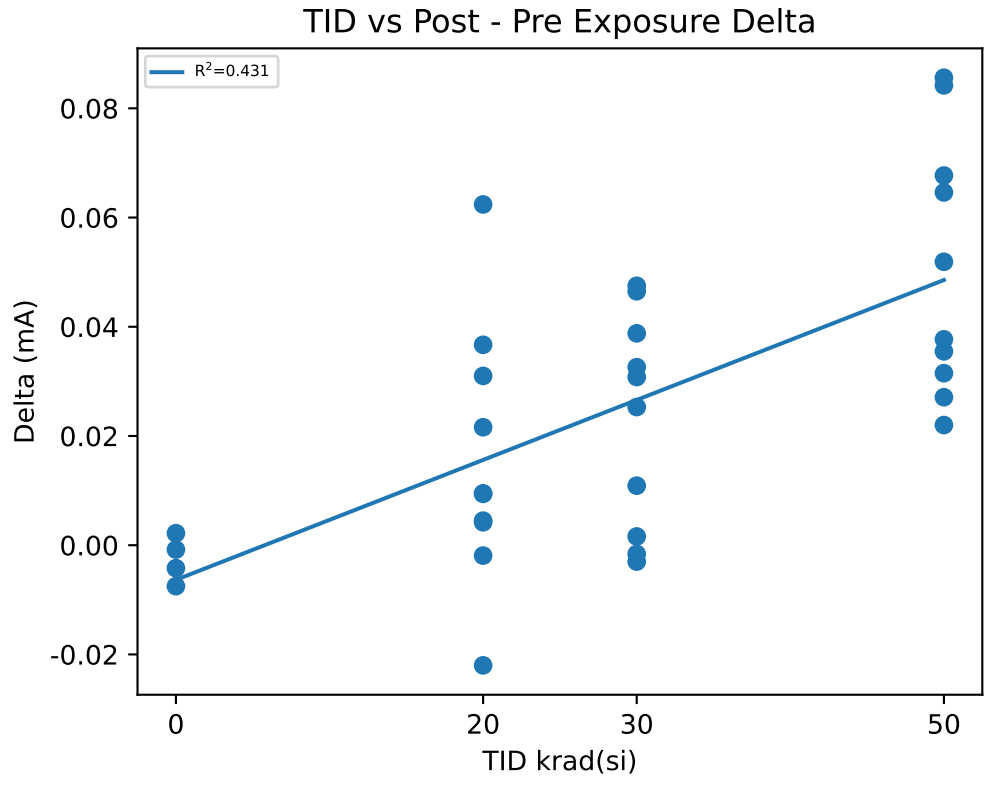
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	3.6194	3.6353	0.0159
2	20	Unbiased	3.6326	3.6228	-0.0098
3	50	Biased	3.5709	3.5783	0.0074
4	30	Unbiased	3.6253	3.6508	0.0255
5	50	Unbiased	3.6819	3.6987	0.0168
6	30	Biased	3.6272	3.6374	0.0102
7	50	Biased	3.699	3.7169	0.0179
8	30	Unbiased	3.6667	3.6883	0.0216
9	20	Unbiased	3.6125	3.6464	0.0339
10	50	Biased	3.6564	3.6669	0.0105
11	30	Biased	3.5775	3.5863	0.0088
12	0	Correlation	3.6616	3.6635	0.0019
13	0	Correlation	3.6969	3.6885	-0.0084
14	50	Unbiased	3.7084	3.7146	0.0062
15	20	Biased	3.66	3.6627	0.0027
16	20	Unbiased	3.6671	3.6785	0.0114
17	20	Biased	3.7043	3.7141	0.0098
18	20	Unbiased	3.6494	3.6531	0.0037
19	20	Biased	3.6214	3.6243	0.0029
20	50	Unbiased	3.7274	3.7661	0.0387
21	0	Correlation	3.6521	3.641	-0.0111
22	50	Unbiased	3.625	3.6527	0.0277
23	0	Correlation	3.6026	3.6026	0
24	20	Biased	3.6257	3.6267	0.001
26	50	Biased	3.654	3.6823	0.0283
27	30	Unbiased	3.6874	3.6831	-0.0043
28	30	Biased	3.6294	3.6419	0.0125
29	30	Unbiased	3.6161	3.6119	-0.0042
30	20	Biased	3.6329	3.6447	0.0118
31	30	Unbiased	3.6034	3.6021	-0.0013
33	30	Biased	3.6377	3.6535	0.0158
34	50	Unbiased	3.6992	3.7129	0.0137
35	20	Unbiased	3.7105	3.6956	-0.0149
41	30	Biased	3.6087	3.6217	0.013

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.6026	3.6533	3.6969	0.038909	3.6026	3.6489	3.6885	0.036457	-0.0111	-0.0044	0.0019	0.006323
20	3.6125	3.6516	3.7105	0.033968	3.6228	3.6569	3.7141	0.031057	-0.0149	0.00525	0.0339	0.01328
30	3.5775	3.6279	3.6874	0.031269	3.5863	3.6377	3.6883	0.033152	-0.0043	0.00976	0.0255	0.010319
50	3.5709	3.6642	3.7274	0.048432	3.5783	3.6825	3.7661	0.052288	0.0062	0.01831	0.0387	0.010327

Device Test: 14.6 IDD|SUPPLY CURRENT/IN/4.5/4.5/0/0/4.5/500kHz//@IDD_ACT_500K_NOLOAD





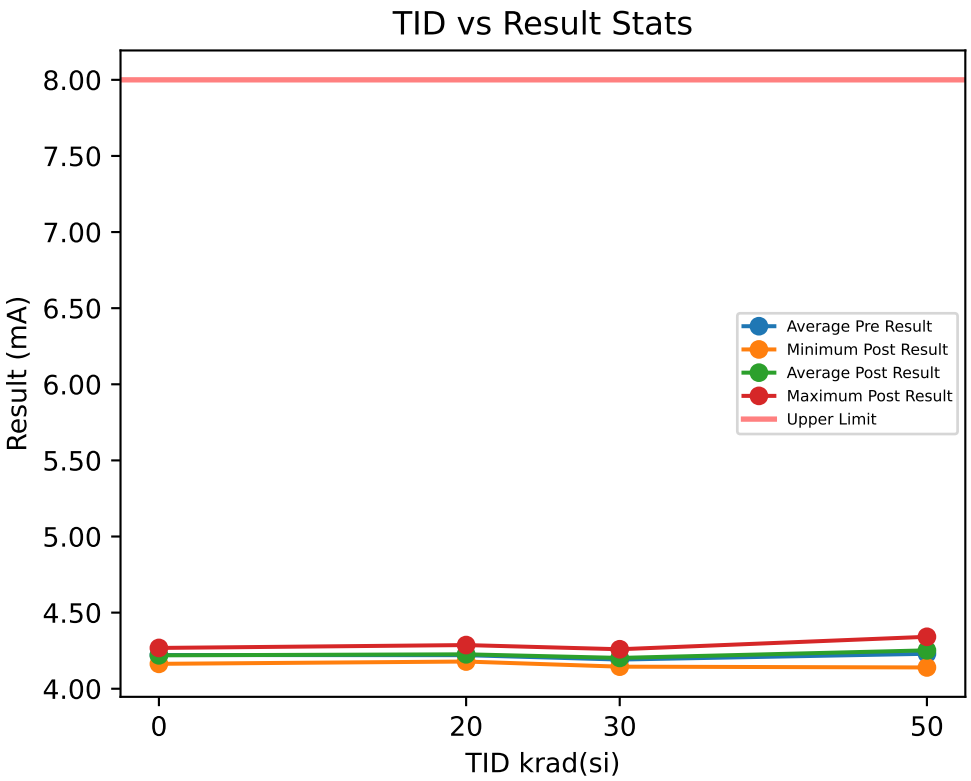
Test Results (Upper Limit = 17.0 (mA))

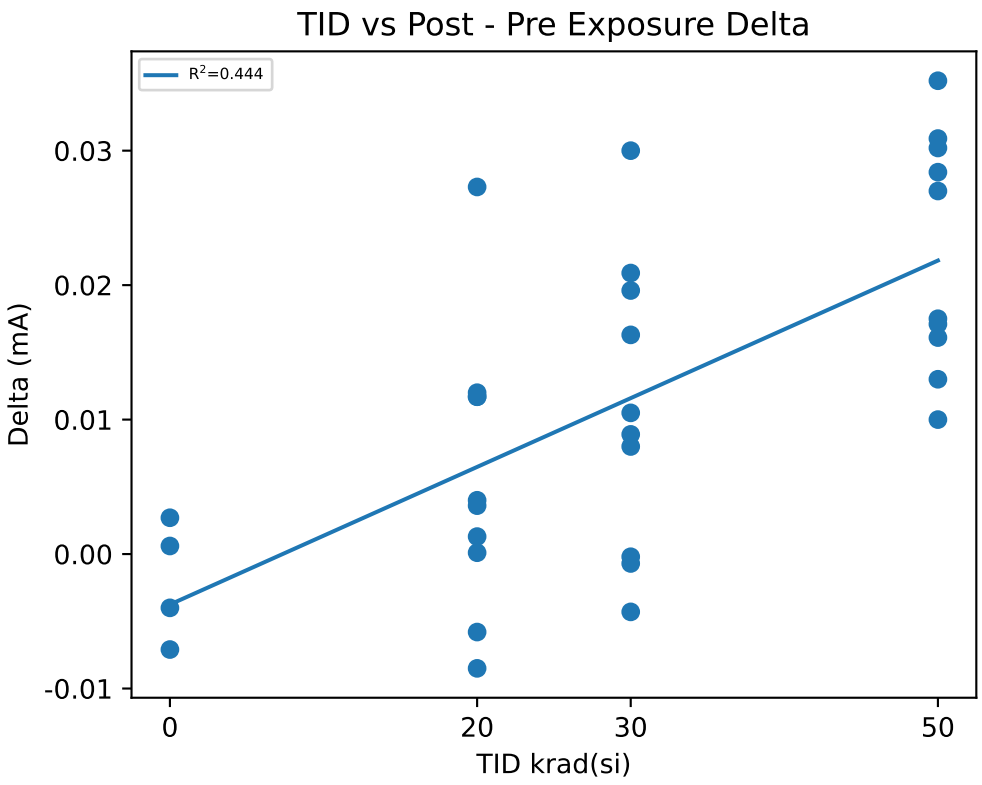
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	6.6419	6.6734	0.0315
2	20	Unbiased	6.6922	6.6903	-0.0019
3	50	Biased	6.627	6.6625	0.0355
4	30	Unbiased	6.67	6.7165	0.0465
5	50	Unbiased	6.7047	6.7424	0.0377
6	30	Biased	6.6153	6.6541	0.0388
7	50	Biased	6.7651	6.8328	0.0677
8	30	Unbiased	6.7276	6.7529	0.0253
9	20	Unbiased	6.6721	6.7345	0.0624
10	50	Biased	6.6676	6.7322	0.0646
11	30	Biased	6.6111	6.622	0.0109
12	0	Correlation	6.6304	6.6326	0.0022
13	0	Correlation	6.7139	6.7064	-0.0075
14	50	Unbiased	6.7778	6.7998	0.022
15	20	Biased	6.6974	6.7016	0.0042
16	20	Unbiased	6.7047	6.7263	0.0216
17	20	Biased	6.7615	6.7925	0.031
18	20	Unbiased	6.7287	6.7332	0.0045
19	20	Biased	6.6888	6.6982	0.0094
20	50	Unbiased	6.8225	6.9067	0.0842
21	0	Correlation	6.6227	6.6185	-0.0042
22	50	Unbiased	6.6321	6.7177	0.0856
23	0	Correlation	6.614	6.6132	-0.0008
24	20	Biased	6.6683	6.6778	0.0095
26	50	Biased	6.66	6.7119	0.0519
27	30	Unbiased	6.7224	6.7208	-0.0016
28	30	Biased	6.7207	6.7515	0.0308
29	30	Unbiased	6.6392	6.6408	0.0016
30	20	Biased	6.6717	6.7084	0.0367
31	30	Unbiased	6.6052	6.6022	-0.003
33	30	Biased	6.6474	6.68	0.0326
34	50	Unbiased	6.717	6.7441	0.0271
35	20	Unbiased	6.7831	6.7611	-0.022
41	30	Biased	6.552	6.5995	0.0475

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.614	6.6452	6.7139	0.046254	6.6132	6.6427	6.7064	0.043265	-0.0075	-0.002575	0.0022	0.0041971
20	6.6683	6.7069	6.7831	0.039217	6.6778	6.7224	6.7925	0.034839	-0.022	0.01554	0.0624	0.02347
30	6.552	6.6511	6.7276	0.058786	6.5995	6.674	6.7529	0.058852	-0.003	0.02294	0.0475	0.019567
50	6.627	6.7016	6.8225	0.067945	6.6625	6.7523	6.9067	0.074732	0.022	0.05078	0.0856	0.023507

Device Test: 14.7 IDD_DIS|STANDBY CURRENT/IN/4.5/4.5/0/0/4.5/500kHz//@IDD_DIS





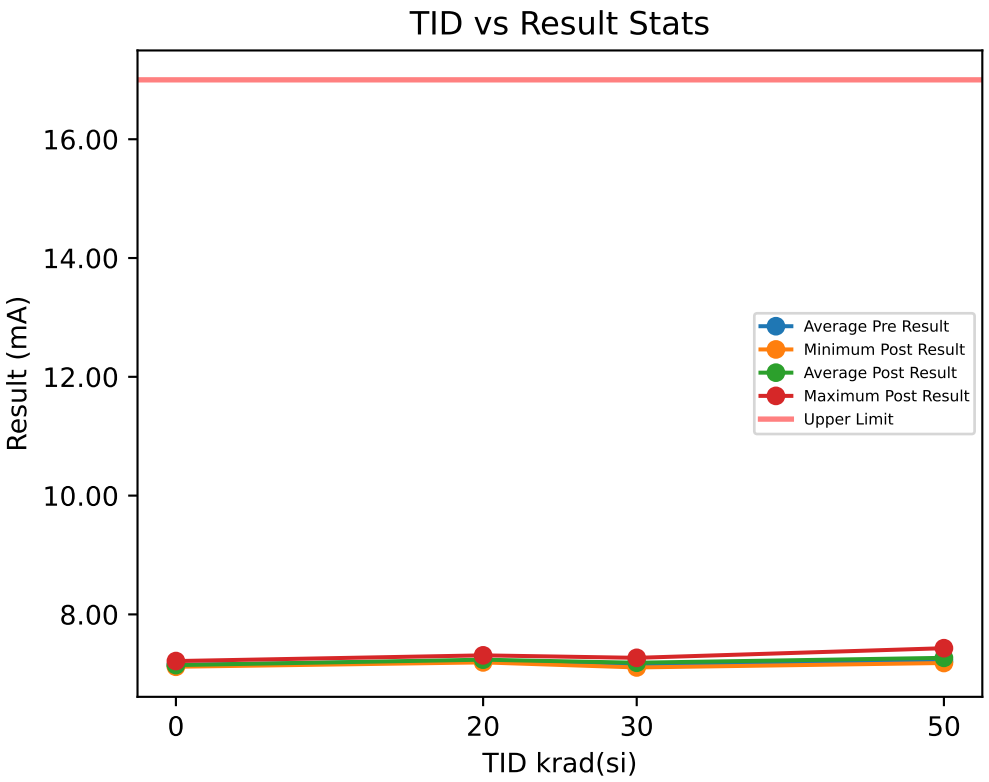
Test Results (Upper Limit = 8.0 (mA))

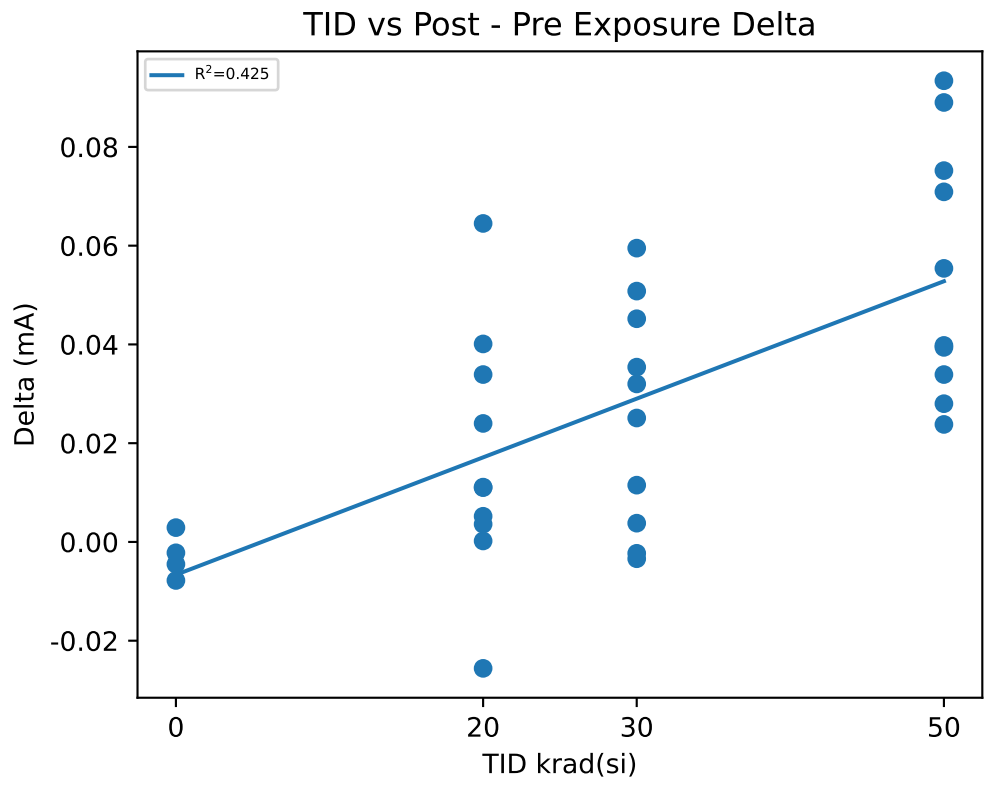
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	4.1833	4.1994	0.0161
2	20	Unbiased	4.1872	4.1787	-0.0085
3	50	Biased	4.1298	4.1398	0.01
4	30	Unbiased	4.1834	4.2134	0.03
5	50	Unbiased	4.2448	4.2732	0.0284
6	30	Biased	4.1897	4.2002	0.0105
7	50	Biased	4.265	4.292	0.027
8	30	Unbiased	4.2385	4.2594	0.0209
9	20	Unbiased	4.1806	4.2079	0.0273
10	50	Biased	4.2187	4.2317	0.013
11	30	Biased	4.1361	4.145	0.0089
12	0	Correlation	4.2368	4.2395	0.0027
13	0	Correlation	4.2751	4.268	-0.0071
14	50	Unbiased	4.2657	4.2832	0.0175
15	20	Biased	4.2322	4.2335	0.0013
16	20	Unbiased	4.2458	4.2578	0.012
17	20	Biased	4.2752	4.2869	0.0117
18	20	Unbiased	4.2114	4.2154	0.004
19	20	Biased	4.1901	4.1902	0.0001
20	50	Unbiased	4.306	4.3412	0.0352
21	0	Correlation	4.2109	4.2069	-0.004
22	50	Unbiased	4.1887	4.2196	0.0309
23	0	Correlation	4.163	4.1636	0.0006
24	20	Biased	4.1935	4.1971	0.0036
26	50	Biased	4.2202	4.2504	0.0302
27	30	Unbiased	4.2543	4.2536	-0.0007
28	30	Biased	4.2028	4.2108	0.008
29	30	Unbiased	4.1692	4.1649	-0.0043
30	20	Biased	4.2083	4.22	0.0117
31	30	Unbiased	4.1616	4.1614	-0.0002
33	30	Biased	4.209	4.2253	0.0163
34	50	Unbiased	4.2739	4.291	0.0171
35	20	Unbiased	4.2799	4.2741	-0.0058
41	30	Biased	4.1709	4.1905	0.0196

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.163	4.2214	4.2751	0.047052	4.1636	4.2195	4.268	0.044855	-0.0071	-0.00195	0.0027	0.0044291
20	4.1806	4.2204	4.2799	0.036337	4.1787	4.2262	4.2869	0.036393	-0.0085	0.00574	0.0273	0.010382
30	4.1361	4.1916	4.2543	0.035809	4.145	4.2025	4.2594	0.038173	-0.0043	0.0109	0.03	0.010909
50	4.1298	4.2296	4.306	0.05225	4.1398	4.2522	4.3412	0.057077	0.01	0.02254	0.0352	0.008742

Device Test: 14.8 IDD|SUPPLY CURRENT/IN/5/5/0/0/5/500kHz//@IDD_ACT_500K_NOLOAD





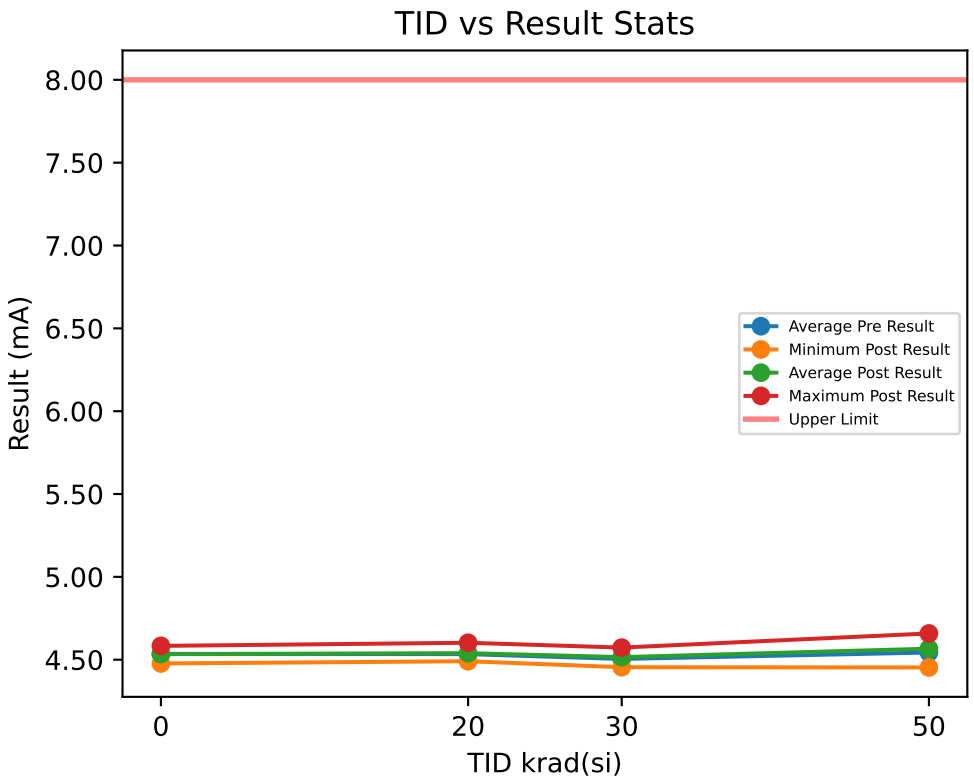
Test Results (Upper Limit = 17.0 (mA))

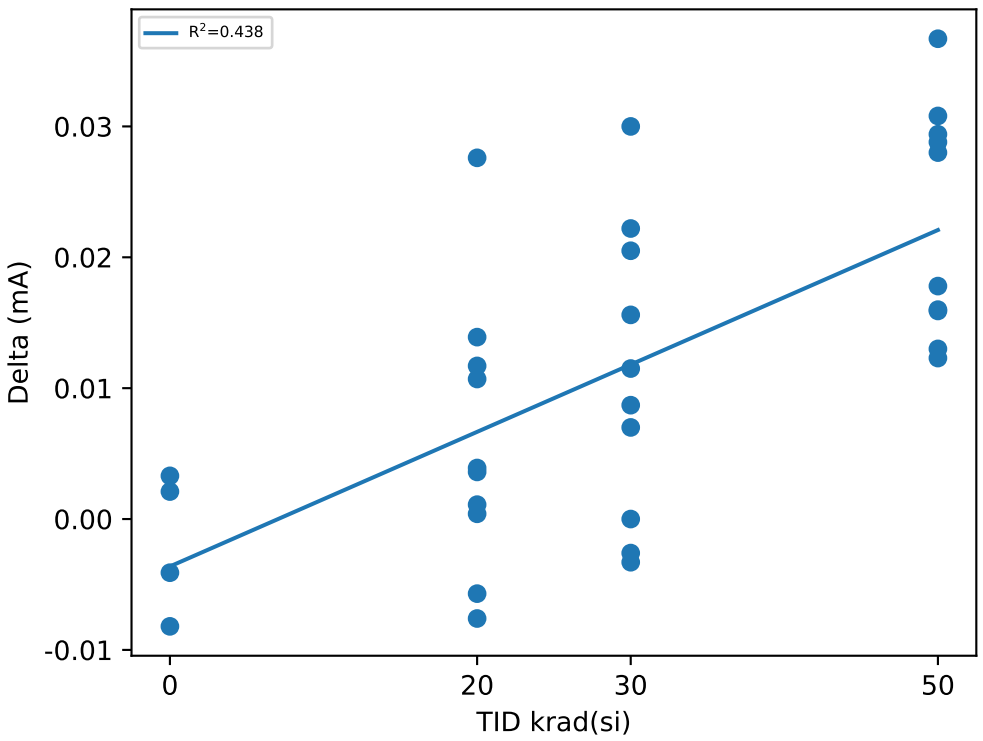
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	7.1502	7.1841	0.0339
2	20	Unbiased	7.2072	7.2074	0.0002
3	50	Biased	7.1425	7.1819	0.0394
4	30	Unbiased	7.1819	7.2327	0.0508
5	50	Unbiased	7.2152	7.255	0.0398
6	30	Biased	7.1202	7.1654	0.0452
7	50	Biased	7.2821	7.353	0.0709
8	30	Unbiased	7.2398	7.2649	0.0251
9	20	Unbiased	7.1851	7.2496	0.0645
10	50	Biased	7.1744	7.2496	0.0752
11	30	Biased	7.123	7.1345	0.0115
12	0	Correlation	7.1279	7.1308	0.0029
13	0	Correlation	7.2223	7.2145	-0.0078
14	50	Unbiased	7.2962	7.32	0.0238
15	20	Biased	7.2092	7.2144	0.0052
16	20	Unbiased	7.2175	7.2415	0.024
17	20	Biased	7.2766	7.3105	0.0339
18	20	Unbiased	7.2451	7.2487	0.0036
19	20	Biased	7.2029	7.214	0.0111
20	50	Unbiased	7.342	7.431	0.089
21	0	Correlation	7.123	7.1185	-0.0045
22	50	Unbiased	7.1425	7.2359	0.0934
23	0	Correlation	7.1237	7.1215	-0.0022
24	20	Biased	7.1809	7.1919	0.011
26	50	Biased	7.1687	7.2241	0.0554
27	30	Unbiased	7.2348	7.2325	-0.0023
28	30	Biased	7.2368	7.2688	0.032
29	30	Unbiased	7.1515	7.1553	0.0038
30	20	Biased	7.1836	7.2237	0.0401
31	30	Unbiased	7.1153	7.1119	-0.0034
33	30	Biased	7.1577	7.1931	0.0354
34	50	Unbiased	7.2255	7.2535	0.028
35	20	Unbiased	7.302	7.2764	-0.0256
41	30	Biased	7.0473	7.1068	0.0595

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.123	7.1492	7.2223	0.048765	7.1185	7.1463	7.2145	0.045751	-0.0078	-0.0029	0.0029	0.0044981
20	7.1809	7.221	7.302	0.041094	7.1919	7.2378	7.3105	0.035576	-0.0256	0.0168	0.0645	0.024968
30	7.0473	7.1608	7.2398	0.063302	7.1068	7.1866	7.2688	0.060785	-0.0034	0.02576	0.0595	0.022605
50	7.1425	7.2139	7.342	0.071358	7.1819	7.2688	7.431	0.077903	0.0238	0.05488	0.0934	0.025633

Device Test: 14.9 IDD_DIS|STANDBY CURRENT/IN/5/5/0/0/5/500kHz//@IDD_DIS





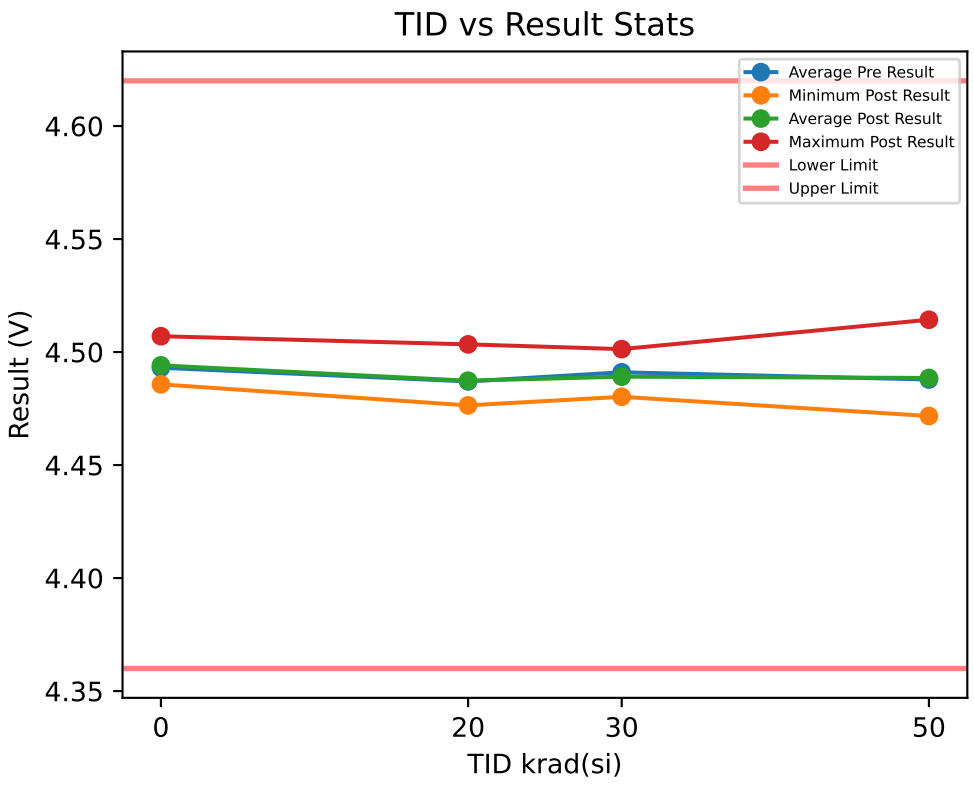
Test Results (Upper Limit = 8.0 (mA))

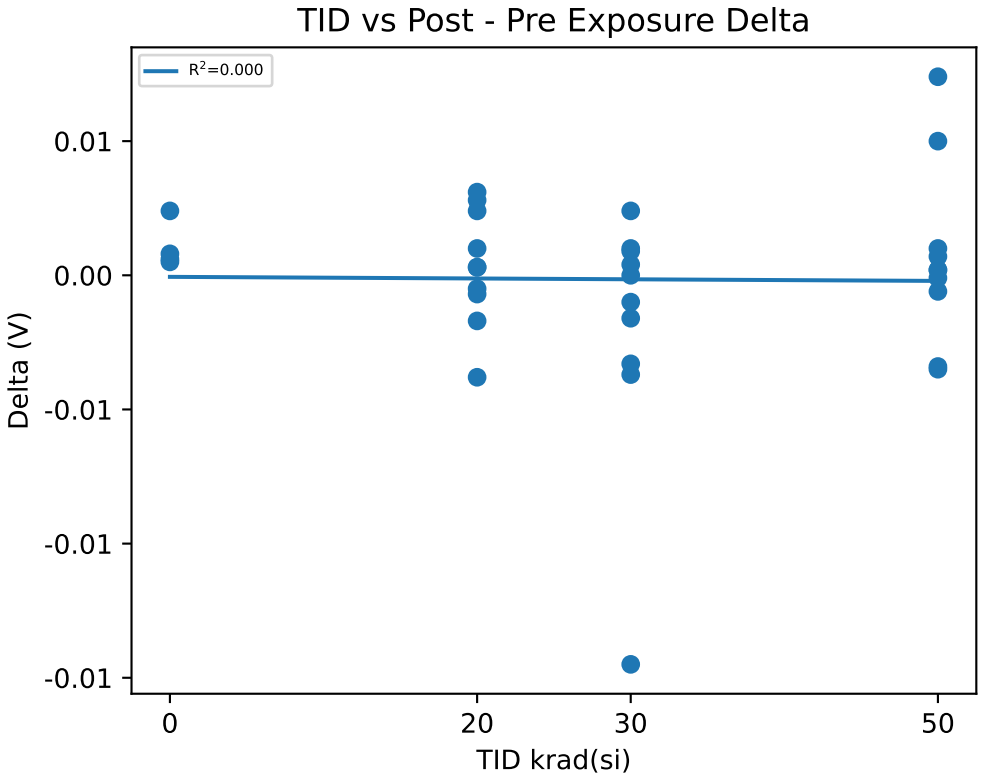
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	4.4941	4.51	0.0159
2	20	Unbiased	4.4984	4.4908	-0.0076
3	50	Biased	4.4409	4.4532	0.0123
4	30	Unbiased	4.4937	4.5237	0.03
5	50	Unbiased	4.5588	4.5882	0.0294
6	30	Biased	4.5026	4.5141	0.0115
7	50	Biased	4.5811	4.6091	0.028
8	30	Unbiased	4.5509	4.5731	0.0222
9	20	Unbiased	4.4928	4.5204	0.0276
10	50	Biased	4.5307	4.5437	0.013
11	30	Biased	4.4477	4.4547	0.007
12	0	Correlation	4.551	4.5543	0.0033
13	0	Correlation	4.5917	4.5835	-0.0082
14	50	Unbiased	4.5807	4.5985	0.0178
15	20	Biased	4.5469	4.5473	0.0004
16	20	Unbiased	4.5589	4.5728	0.0139
17	20	Biased	4.5906	4.6023	0.0117
18	20	Unbiased	4.5264	4.5303	0.0039
19	20	Biased	4.5007	4.5018	0.0011
20	50	Unbiased	4.6217	4.6584	0.0367
21	0	Correlation	4.5231	4.519	-0.0041
22	50	Unbiased	4.5027	4.5315	0.0288
23	0	Correlation	4.4752	4.4773	0.0021
24	20	Biased	4.5056	4.5092	0.0036
26	50	Biased	4.5342	4.565	0.0308
27	30	Unbiased	4.5707	4.5674	-0.0033
28	30	Biased	4.516	4.5247	0.0087
29	30	Unbiased	4.4797	4.4771	-0.0026
30	20	Biased	4.522	4.5327	0.0107
31	30	Unbiased	4.476	4.476	0
33	30	Biased	4.5229	4.5385	0.0156
34	50	Unbiased	4.5898	4.6058	0.016
35	20	Unbiased	4.593	4.5873	-0.0057
41	30	Biased	4.4857	4.5062	0.0205

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.4752	4.5353	4.5917	0.04895	4.4773	4.5335	4.5835	0.045831	-0.0082	-0.001725	0.0033	0.005399
20	4.4928	4.5335	4.593	0.037343	4.4908	4.5395	4.6023	0.037424	-0.0076	0.00596	0.0276	0.010387
30	4.4477	4.5046	4.5707	0.036717	4.4547	4.5156	4.5731	0.038747	-0.0033	0.01096	0.03	0.011204
50	4.4409	4.5435	4.6217	0.053927	4.4532	4.5663	4.6584	0.058761	0.0123	0.02287	0.0367	0.008749

Device Test: 15.1 VLDO|V_VLDO/VLDO/5/5/0/0/4.5/500kHz//@V_LDO_4P5





Test Results (Lower Limit = 4.36, Upper Limit = 4.62 (V))

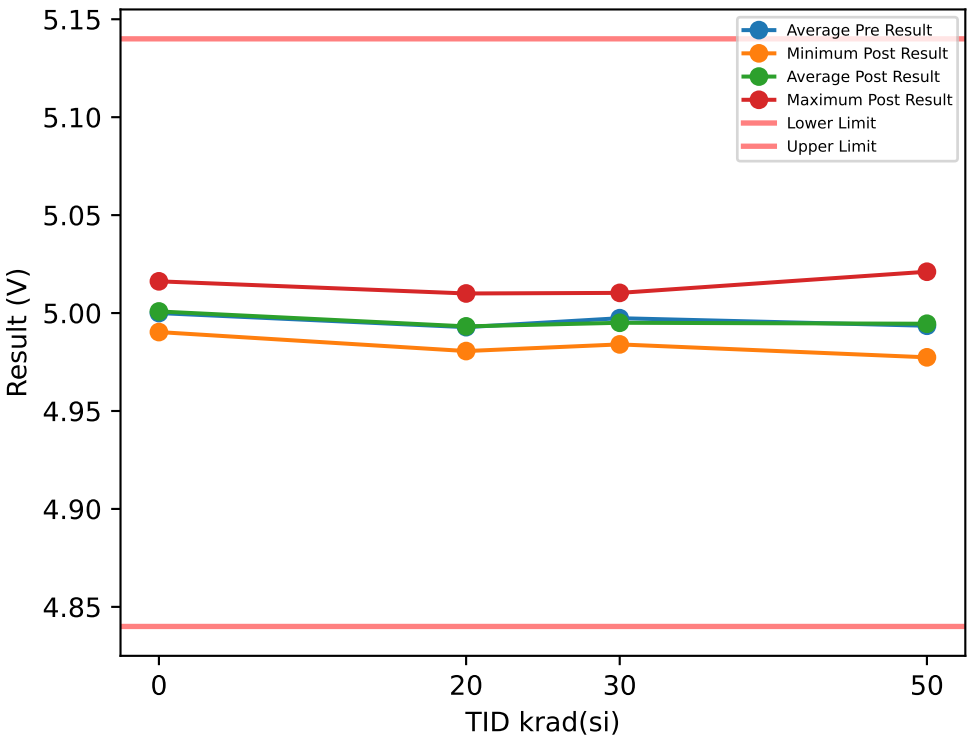
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	4.4876	4.487	-0.0006
2	20	Unbiased	4.4909	4.4892	-0.0017
3	50	Biased	4.4992	4.4957	-0.0035
4	30	Unbiased	4.4862	4.4852	-0.001
5	50	Unbiased	4.4707	4.4717	0.001
6	30	Biased	4.4864	4.4848	-0.0016
7	50	Biased	4.4911	4.491	-0.0001
8	30	Unbiased	4.4835	4.4802	-0.0033
9	20	Unbiased	4.4767	4.4777	0.001
10	50	Biased	4.4816	4.4818	0.0002
11	30	Biased	4.491	4.492	0.001
12	0	Correlation	4.4854	4.4862	0.0008
13	0	Correlation	4.5064	4.507	0.0006
14	50	Unbiased	4.4833	4.4799	-0.0034
15	20	Biased	4.4771	4.4764	-0.0007
16	20	Unbiased	4.4906	4.4937	0.0031
17	20	Biased	4.4848	4.4876	0.0028
18	20	Unbiased	4.4831	4.4793	-0.0038
19	20	Biased	4.4872	4.4875	0.0003
20	50	Unbiased	4.5069	4.5143	0.0074
21	0	Correlation	4.4833	4.4857	0.0024
22	50	Unbiased	4.4873	4.488	0.0007
23	0	Correlation	4.4971	4.4976	0.0005
24	20	Biased	4.5031	4.5034	0.0003
26	50	Biased	4.4827	4.4877	0.005
27	30	Unbiased	4.4818	4.4818	0
28	30	Biased	4.5035	4.4998	-0.0037
29	30	Unbiased	4.4926	4.4935	0.0009
30	20	Biased	4.484	4.4864	0.0024
31	30	Unbiased	4.4857	4.4861	0.0004
33	30	Biased	4.4989	4.5013	0.0024
34	50	Unbiased	4.4881	4.4883	0.0002
35	20	Unbiased	4.4925	4.492	-0.0005
41	30	Biased	4.5008	4.4863	-0.0145

Test Statistics (V)

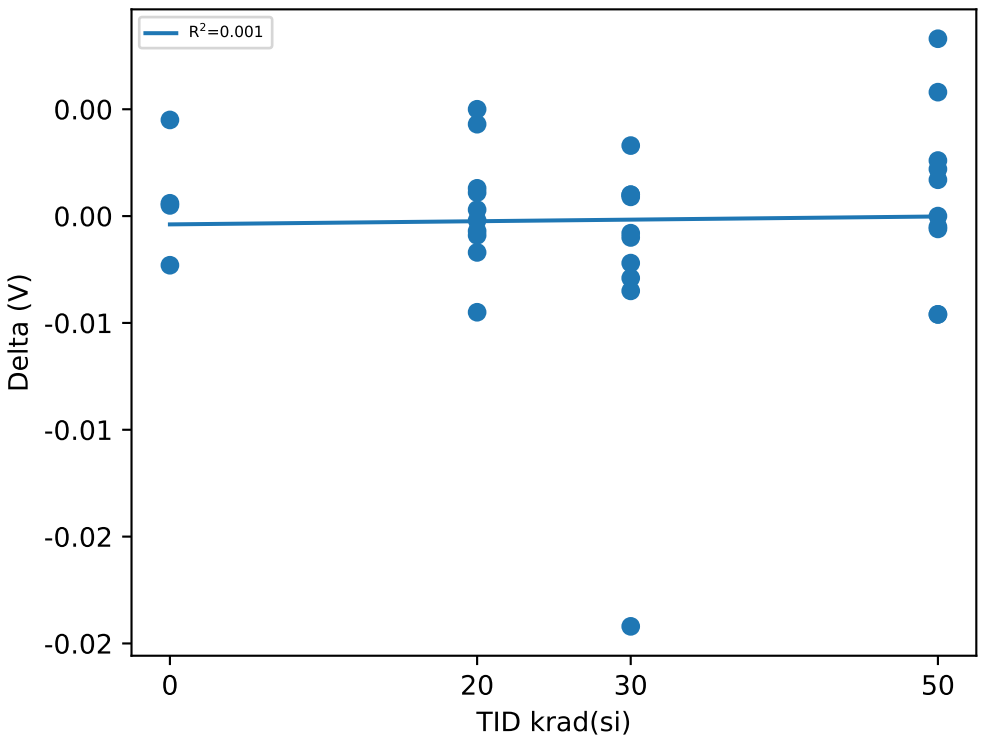
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.4833	4.4931	4.5064	0.010774	4.4857	4.4941	4.507	0.010192	0.0005	0.001075	0.0024	0.00089209
20	4.4767	4.487	4.5031	0.0078232	4.4764	4.4873	4.5034	0.008177	-0.0038	0.00032	0.0031	0.0021457
30	4.4818	4.491	4.5035	0.007677	4.4802	4.4891	4.5013	0.0072583	-0.0145	-0.00194	0.0024	0.004813
50	4.4707	4.4878	4.5069	0.0099058	4.4717	4.4885	4.5143	0.011195	-0.0035	0.00069	0.0074	0.0033458

Device Test: 15.11 VLDO|V_VLDO/VLDO/12/12/0/0/5/500kHz//@V_LDO_5

TID vs Result Stats



TID vs Post - Pre Exposure Delta



Test Results (Lower Limit = 4.84, Upper Limit = 5.14 (V))

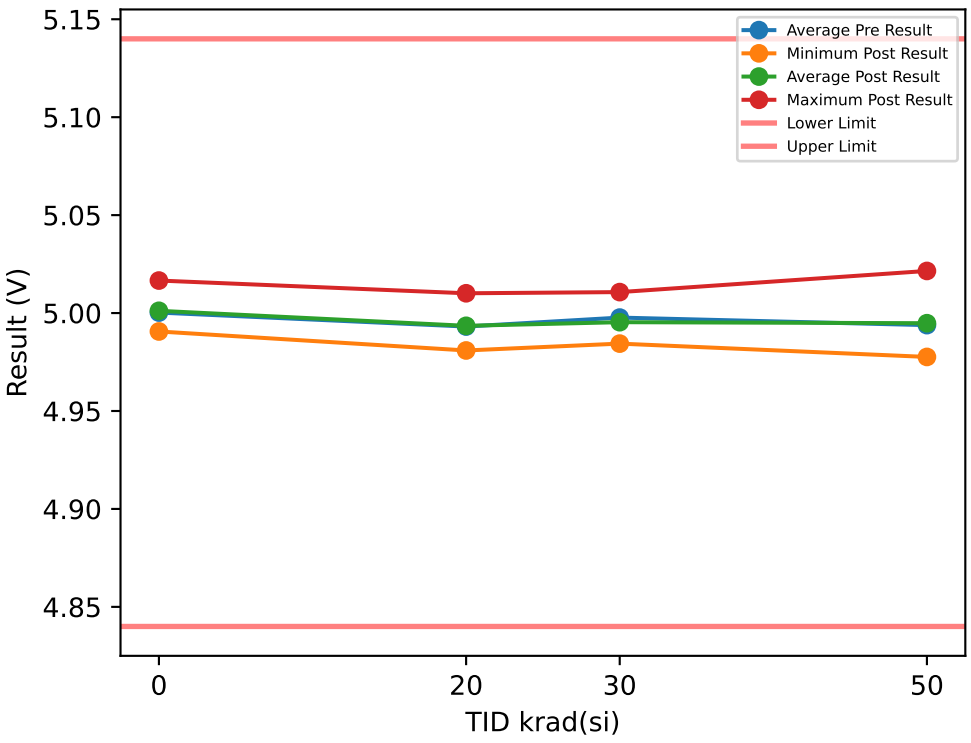
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	4.9944	4.9939	-0.0005
2	20	Unbiased	4.9961	4.9964	0.0003
3	50	Biased	5.0081	5.0035	-0.0046
4	30	Unbiased	4.9899	4.9889	-0.001
5	50	Unbiased	4.9757	4.9774	0.0017
6	30	Biased	4.9911	4.992	0.0009
7	50	Biased	4.9989	4.9983	-0.0006
8	30	Unbiased	4.9869	4.984	-0.0029
9	20	Unbiased	4.9823	4.9806	-0.0017
10	50	Biased	4.9858	4.9884	0.0026
11	30	Biased	4.999	5	0.001
12	0	Correlation	4.989	4.9935	0.0045
13	0	Correlation	5.0157	5.0162	0.0005
14	50	Unbiased	4.9875	4.9829	-0.0046
15	20	Biased	4.9833	4.9824	-0.0009
16	20	Unbiased	4.9949	4.9992	0.0043
17	20	Biased	4.9913	4.9924	0.0011
18	20	Unbiased	4.9875	4.983	-0.0045
19	20	Biased	4.9946	4.9944	-0.0002
20	50	Unbiased	5.0128	5.0211	0.0083
21	0	Correlation	4.9897	4.9903	0.0006
22	50	Unbiased	4.9921	4.9921	0
23	0	Correlation	5.0056	5.0033	-0.0023
24	20	Biased	5.0087	5.01	0.0013
26	50	Biased	4.9867	4.9925	0.0058
27	30	Unbiased	4.9886	4.9851	-0.0035
28	30	Biased	5.0091	5.0083	-0.0008
29	30	Unbiased	5	5.001	0.001
30	20	Biased	4.9886	4.9936	0.005
31	30	Unbiased	4.9929	4.9907	-0.0022
33	30	Biased	5.007	5.0103	0.0033
34	50	Unbiased	4.9932	4.9954	0.0022
35	20	Unbiased	5.0007	5	-0.0007
41	30	Biased	5.0093	4.9901	-0.0192

Test Statistics (V)

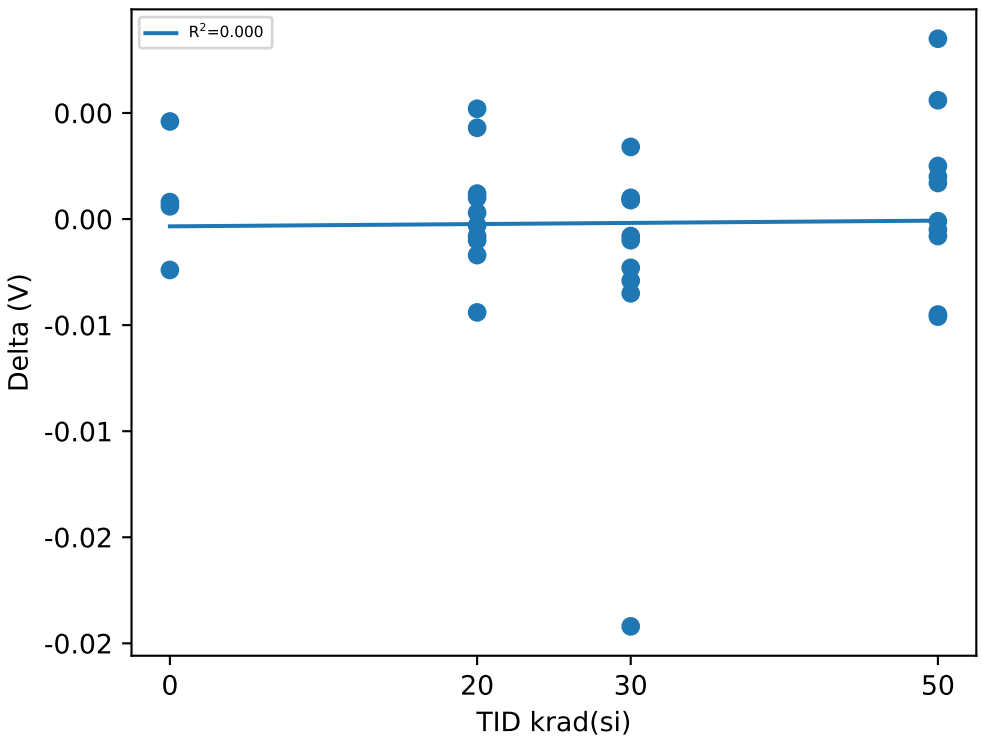
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.989	5	5.0157	0.012974	4.9903	5.0008	5.0162	0.011647	-0.0023	0.000825	0.0045	0.0027945
20	4.9823	4.9928	5.0087	0.0080432	4.9806	4.9932	5.01	0.0091676	-0.0045	0.0004	0.005	0.0027761
30	4.9869	4.9974	5.0093	0.0087169	4.984	4.995	5.0103	0.0093076	-0.0192	-0.00234	0.0033	0.006278
50	4.9757	4.9935	5.0128	0.010934	4.9774	4.9946	5.0211	0.011917	-0.0046	0.00103	0.0083	0.0040735

Device Test: 15.12 VLDO|V_VLDO/VLDO/14/14/0/0/5/500kHz//@V_LDO_5

TID vs Result Stats



TID vs Post - Pre Exposure Delta



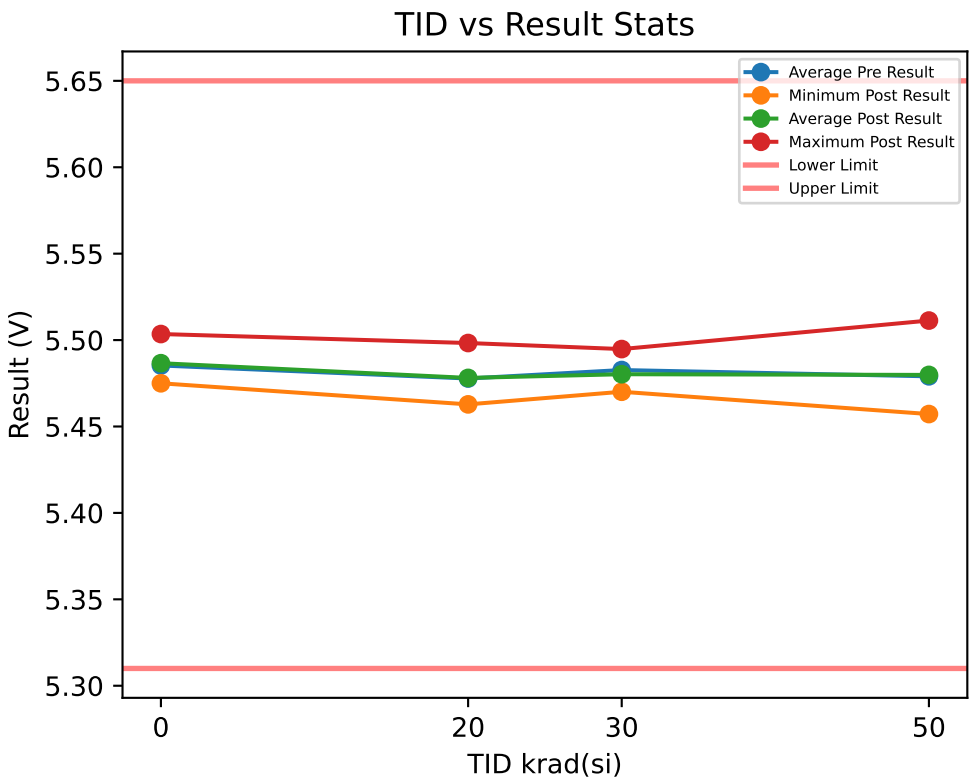
Test Results (Lower Limit = 4.84, Upper Limit = 5.14 (V))

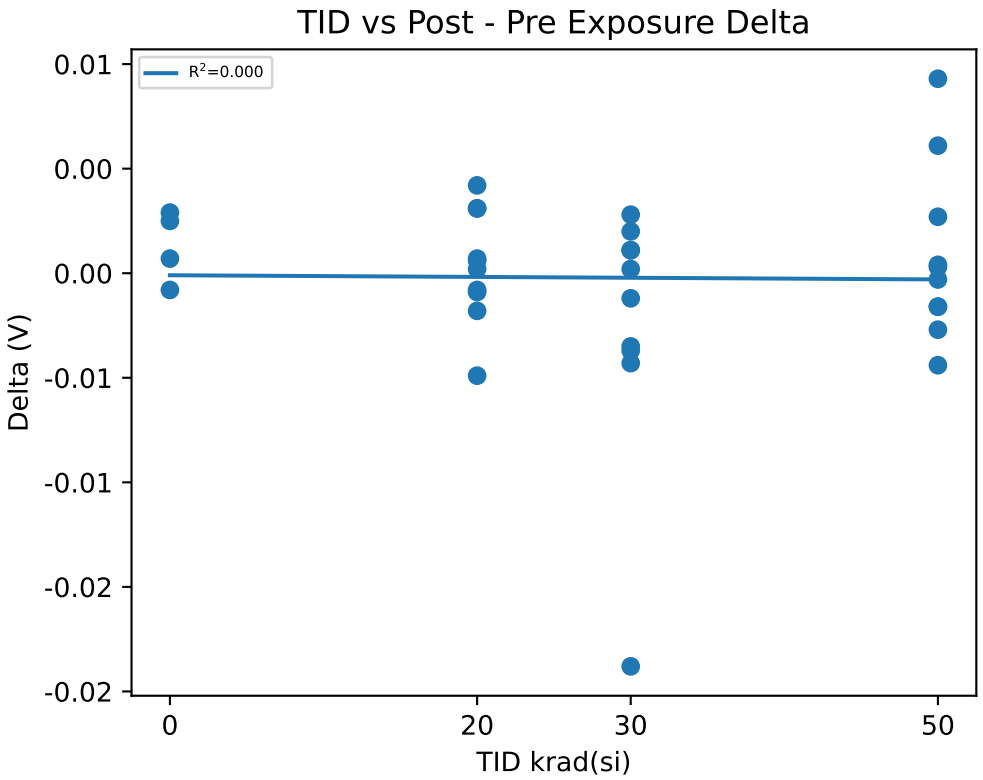
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	4.9947	4.9942	-0.0005
2	20	Unbiased	4.9964	4.9967	0.0003
3	50	Biased	5.0083	5.0038	-0.0045
4	30	Unbiased	4.9902	4.9892	-0.001
5	50	Unbiased	4.9759	4.9776	0.0017
6	30	Biased	4.9914	4.9923	0.0009
7	50	Biased	4.9994	4.9986	-0.0008
8	30	Unbiased	4.9873	4.9844	-0.0029
9	20	Unbiased	4.9826	4.9809	-0.0017
10	50	Biased	4.9861	4.9886	0.0025
11	30	Biased	4.9993	5.0002	0.0009
12	0	Correlation	4.9892	4.9938	0.0046
13	0	Correlation	5.0158	5.0166	0.0008
14	50	Unbiased	4.9878	4.9832	-0.0046
15	20	Biased	4.9837	4.9827	-0.001
16	20	Unbiased	4.9951	4.9994	0.0043
17	20	Biased	4.9917	4.9927	0.001
18	20	Unbiased	4.9878	4.9834	-0.0044
19	20	Biased	4.995	4.9947	-0.0003
20	50	Unbiased	5.013	5.0215	0.0085
21	0	Correlation	4.99	4.9906	0.0006
22	50	Unbiased	4.9924	4.9923	-0.0001
23	0	Correlation	5.006	5.0036	-0.0024
24	20	Biased	5.0089	5.0101	0.0012
26	50	Biased	4.9872	4.9928	0.0056
27	30	Unbiased	4.9889	4.9854	-0.0035
28	30	Biased	5.0094	5.0086	-0.0008
29	30	Unbiased	5.0003	5.0013	0.001
30	20	Biased	4.9888	4.994	0.0052
31	30	Unbiased	4.9932	4.9909	-0.0023
33	30	Biased	5.0073	5.0107	0.0034
34	50	Unbiased	4.9936	4.9956	0.002
35	20	Unbiased	5.0011	5.0003	-0.0008
41	30	Biased	5.0096	4.9904	-0.0192

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9892	5.0003	5.0158	0.012936	4.9906	5.0011	5.0166	0.011691	-0.0024	0.0009	0.0046	0.0028682
20	4.9826	4.9931	5.0089	0.0080228	4.9809	4.9935	5.0101	0.0091079	-0.0044	0.00038	0.0052	0.0028007
30	4.9873	4.9977	5.0096	0.0087036	4.9844	4.9953	5.0107	0.0093121	-0.0192	-0.00235	0.0034	0.0062821
50	4.9759	4.9938	5.013	0.010915	4.9776	4.9948	5.0215	0.011965	-0.0046	0.00098	0.0085	0.0040751

Device Test: 15.15 VLDO|V_VLDO/VLDO/6/6/0/0/5.5/500kHz//@V_LDO_5P5





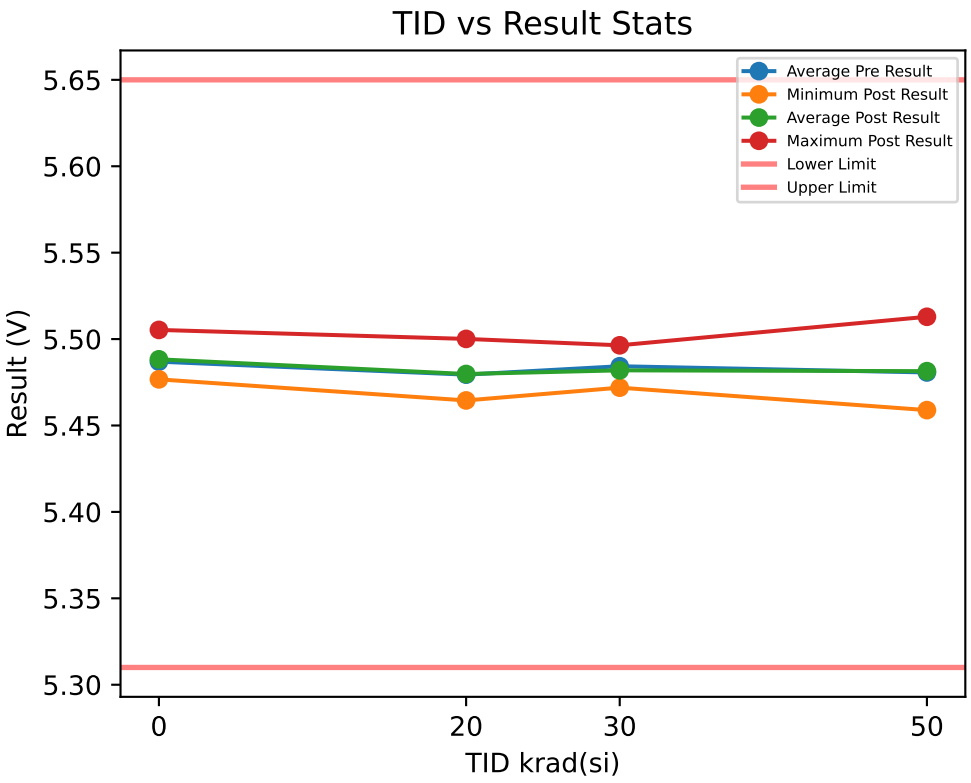
Test Results (Lower Limit = 5.31, Upper Limit = 5.65 (V))

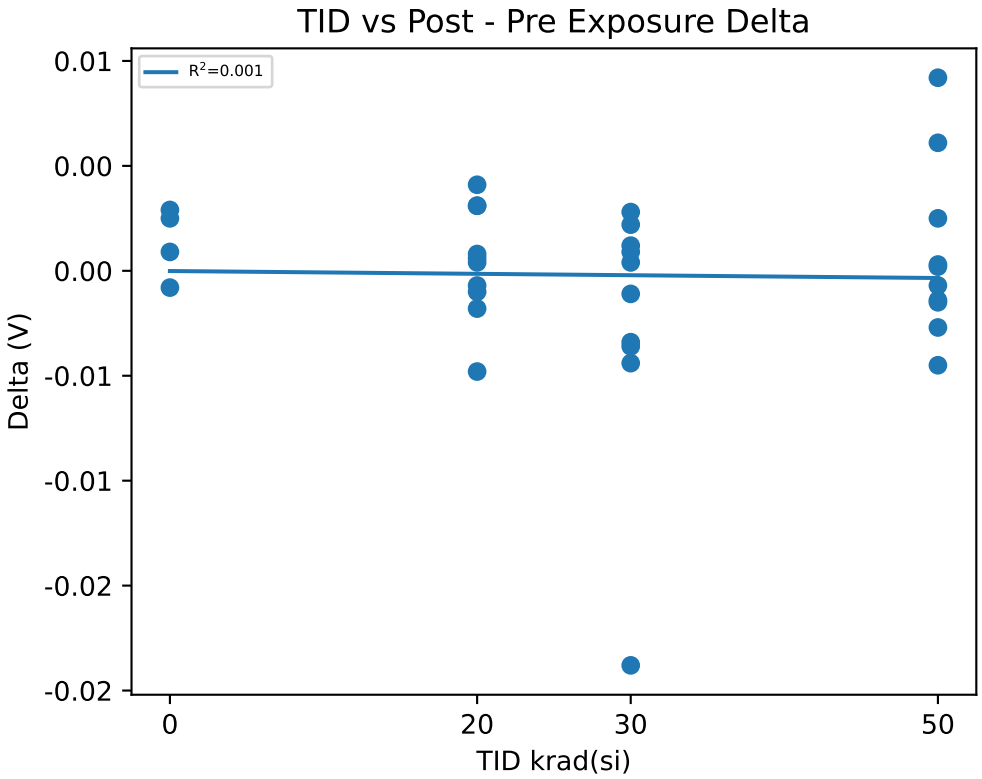
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	5.4793	5.479	-0.0003
2	20	Unbiased	5.4833	5.4815	-0.0018
3	50	Biased	5.4911	5.4895	-0.0016
4	30	Unbiased	5.4769	5.4757	-0.0012
5	50	Unbiased	5.4588	5.4572	-0.0016
6	30	Biased	5.4778	5.4735	-0.0043
7	50	Biased	5.4812	5.4839	0.0027
8	30	Unbiased	5.4738	5.4701	-0.0037
9	20	Unbiased	5.4662	5.4668	0.0006
10	50	Biased	5.4719	5.4692	-0.0027
11	30	Biased	5.4812	5.4823	0.0011
12	0	Correlation	5.4758	5.475	-0.0008
13	0	Correlation	5.5028	5.5035	0.0007
14	50	Unbiased	5.4737	5.4693	-0.0044
15	20	Biased	5.4637	5.4628	-0.0009
16	20	Unbiased	5.4824	5.4866	0.0042
17	20	Biased	5.476	5.4791	0.0031
18	20	Unbiased	5.4739	5.469	-0.0049
19	20	Biased	5.4763	5.4794	0.0031
20	50	Unbiased	5.502	5.5113	0.0093
21	0	Correlation	5.4742	5.4767	0.0025
22	50	Unbiased	5.4789	5.4793	0.0004
23	0	Correlation	5.4884	5.4913	0.0029
24	20	Biased	5.4976	5.4983	0.0007
26	50	Biased	5.4732	5.4793	0.0061
27	30	Unbiased	5.4697	5.4717	0.002
28	30	Biased	5.4983	5.4948	-0.0035
29	30	Unbiased	5.4856	5.4867	0.0011
30	20	Biased	5.4751	5.4753	0.0002
31	30	Unbiased	5.4744	5.4772	0.0028
33	30	Biased	5.4933	5.4935	0.0002
34	50	Unbiased	5.4802	5.4805	0.0003
35	20	Unbiased	5.4831	5.4823	-0.0008
41	30	Biased	5.4957	5.4769	-0.0188

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.4742	5.4853	5.5028	0.013283	5.475	5.4866	5.5035	0.01342	-0.0008	0.001325	0.0029	0.0017095
20	5.4637	5.4778	5.4976	0.0096199	5.4628	5.4781	5.4983	0.010353	-0.0049	0.00035	0.0042	0.0026921
30	5.4697	5.4827	5.4983	0.010056	5.4701	5.4802	5.4948	0.0087938	-0.0188	-0.00243	0.0028	0.0062766
50	5.4588	5.479	5.502	0.011556	5.4572	5.4799	5.5113	0.014291	-0.0044	0.00082	0.0093	0.0041683

Device Test: 15.18 VLDO|V_VLDO/VLDO/12/12/0/0/5.5/500kHz//@V_LDO_5P5





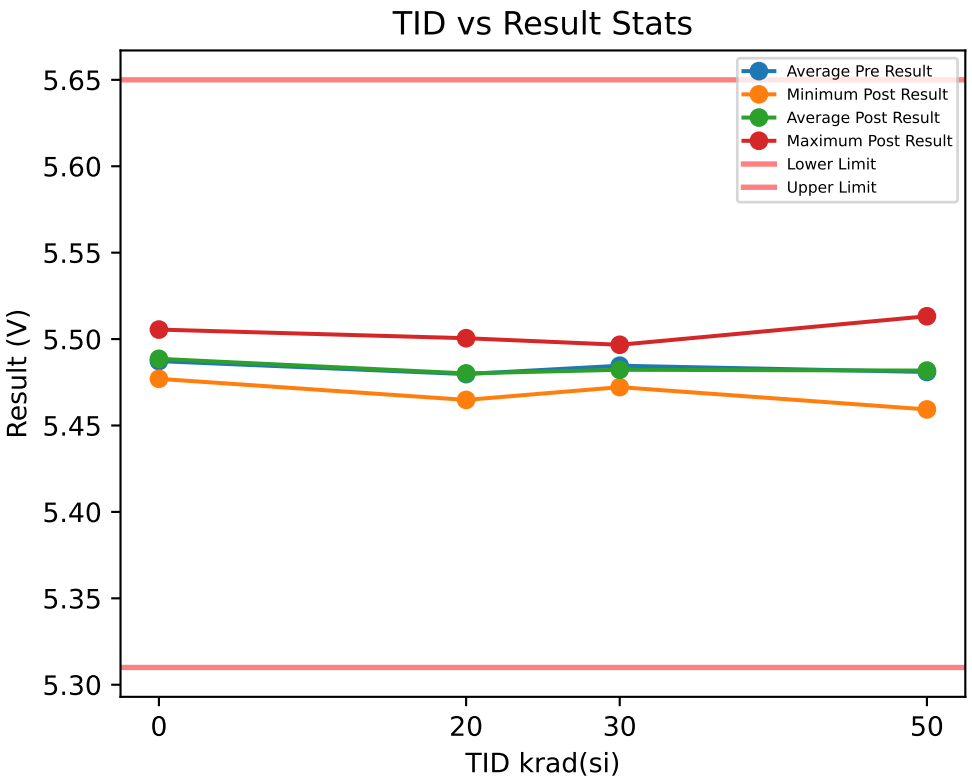
Test Results (Lower Limit = 5.31, Upper Limit = 5.65 (V))

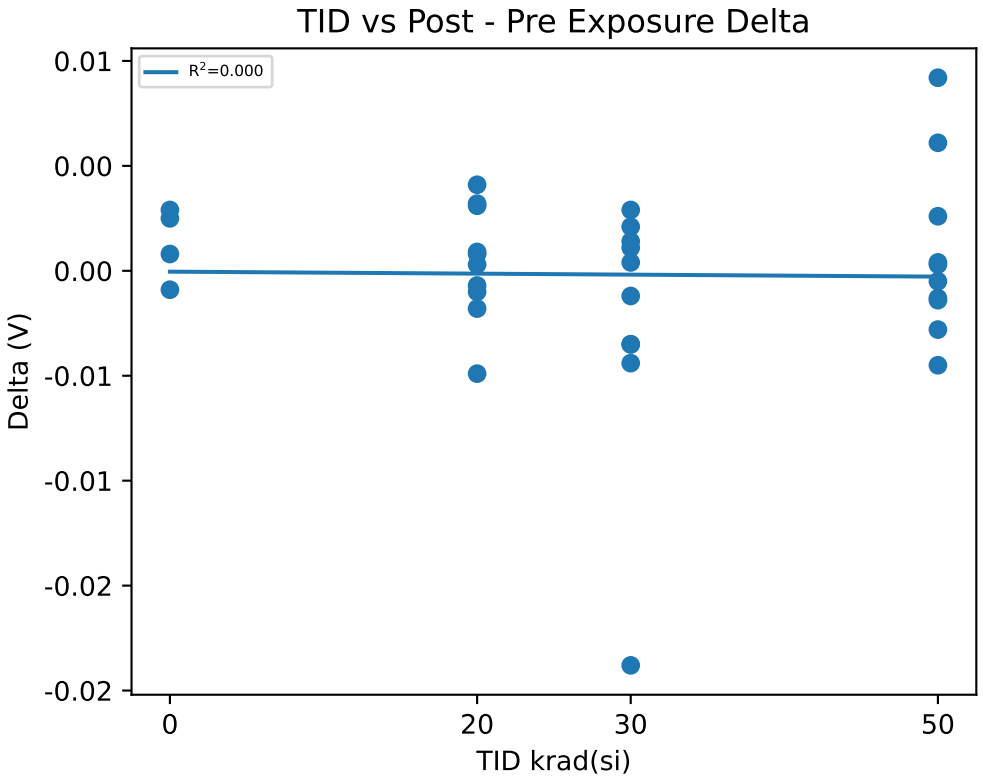
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	5.4811	5.4804	-0.0007
2	20	Unbiased	5.4849	5.4831	-0.0018
3	50	Biased	5.4927	5.4912	-0.0015
4	30	Unbiased	5.4786	5.4775	-0.0011
5	50	Unbiased	5.4603	5.4589	-0.0014
6	30	Biased	5.4795	5.4751	-0.0044
7	50	Biased	5.4829	5.4854	0.0025
8	30	Unbiased	5.4755	5.4719	-0.0036
9	20	Unbiased	5.4677	5.4683	0.0006
10	50	Biased	5.4736	5.4709	-0.0027
11	30	Biased	5.4829	5.4838	0.0009
12	0	Correlation	5.4775	5.4767	-0.0008
13	0	Correlation	5.5044	5.5053	0.0009
14	50	Unbiased	5.4754	5.4709	-0.0045
15	20	Biased	5.4655	5.4645	-0.001
16	20	Unbiased	5.4842	5.4883	0.0041
17	20	Biased	5.4777	5.4808	0.0031
18	20	Unbiased	5.4755	5.4707	-0.0048
19	20	Biased	5.478	5.4811	0.0031
20	50	Unbiased	5.5037	5.5129	0.0092
21	0	Correlation	5.4759	5.4784	0.0025
22	50	Unbiased	5.4805	5.4808	0.0003
23	0	Correlation	5.4899	5.4928	0.0029
24	20	Biased	5.4993	5.5001	0.0008
26	50	Biased	5.4748	5.4809	0.0061
27	30	Unbiased	5.4712	5.4734	0.0022
28	30	Biased	5.4998	5.4964	-0.0034
29	30	Unbiased	5.4872	5.4884	0.0012
30	20	Biased	5.4766	5.477	0.0004
31	30	Unbiased	5.476	5.4788	0.0028
33	30	Biased	5.4948	5.4952	0.0004
34	50	Unbiased	5.4819	5.4821	0.0002
35	20	Unbiased	5.4848	5.4841	-0.0007
41	30	Biased	5.4974	5.4786	-0.0188

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.4759	5.4869	5.5044	0.013224	5.4767	5.4883	5.5053	0.013439	-0.0008	0.001375	0.0029	0.0016879
20	5.4655	5.4794	5.4993	0.0096405	5.4645	5.4798	5.5001	0.0104	-0.0048	0.00038	0.0041	0.0026566
30	5.4712	5.4843	5.4998	0.010033	5.4719	5.4819	5.4964	0.0087645	-0.0188	-0.00238	0.0028	0.0062979
50	5.4603	5.4807	5.5037	0.01159	5.4589	5.4814	5.5129	0.014272	-0.0045	0.00075	0.0092	0.0041479

Device Test: 15.19 VLDO|V_VLDO/VLDO/14/14/0/0/5.5/500kHz//@V_LDO_5P5





Test Results (Lower Limit = 5.31, Upper Limit = 5.65 (V))

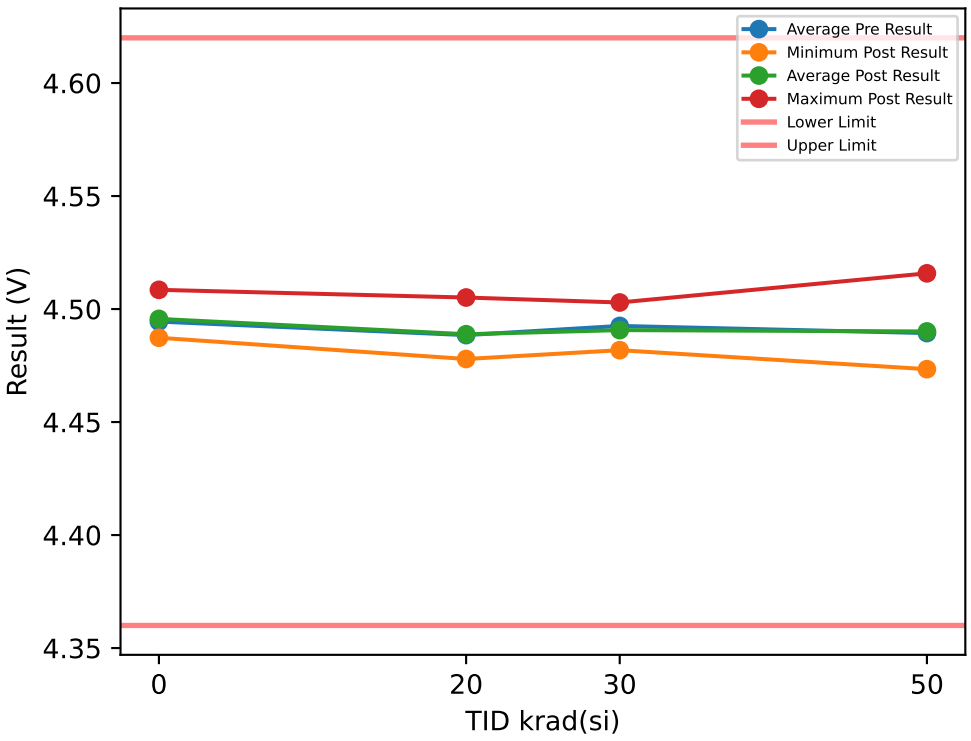
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	5.4812	5.4807	-0.0005
2	20	Unbiased	5.4853	5.4835	-0.0018
3	50	Biased	5.4929	5.4915	-0.0014
4	30	Unbiased	5.4789	5.4777	-0.0012
5	50	Unbiased	5.4606	5.4593	-0.0013
6	30	Biased	5.4798	5.4754	-0.0044
7	50	Biased	5.4831	5.4857	0.0026
8	30	Unbiased	5.4757	5.4722	-0.0035
9	20	Unbiased	5.468	5.4688	0.0008
10	50	Biased	5.474	5.4712	-0.0028
11	30	Biased	5.4831	5.4842	0.0011
12	0	Correlation	5.4779	5.477	-0.0009
13	0	Correlation	5.5047	5.5055	0.0008
14	50	Unbiased	5.4757	5.4712	-0.0045
15	20	Biased	5.4658	5.4648	-0.001
16	20	Unbiased	5.4845	5.4886	0.0041
17	20	Biased	5.478	5.4812	0.0032
18	20	Unbiased	5.4759	5.471	-0.0049
19	20	Biased	5.4783	5.4814	0.0031
20	50	Unbiased	5.504	5.5132	0.0092
21	0	Correlation	5.4762	5.4787	0.0025
22	50	Unbiased	5.4809	5.4812	0.0003
23	0	Correlation	5.4902	5.4931	0.0029
24	20	Biased	5.4996	5.5005	0.0009
26	50	Biased	5.4751	5.4812	0.0061
27	30	Unbiased	5.4715	5.4736	0.0021
28	30	Biased	5.5002	5.4967	-0.0035
29	30	Unbiased	5.4874	5.4888	0.0014
30	20	Biased	5.477	5.4773	0.0003
31	30	Unbiased	5.4763	5.4792	0.0029
33	30	Biased	5.4952	5.4956	0.0004
34	50	Unbiased	5.4821	5.4825	0.0004
35	20	Unbiased	5.485	5.4843	-0.0007
41	30	Biased	5.4978	5.479	-0.0188

Test Statistics (V)

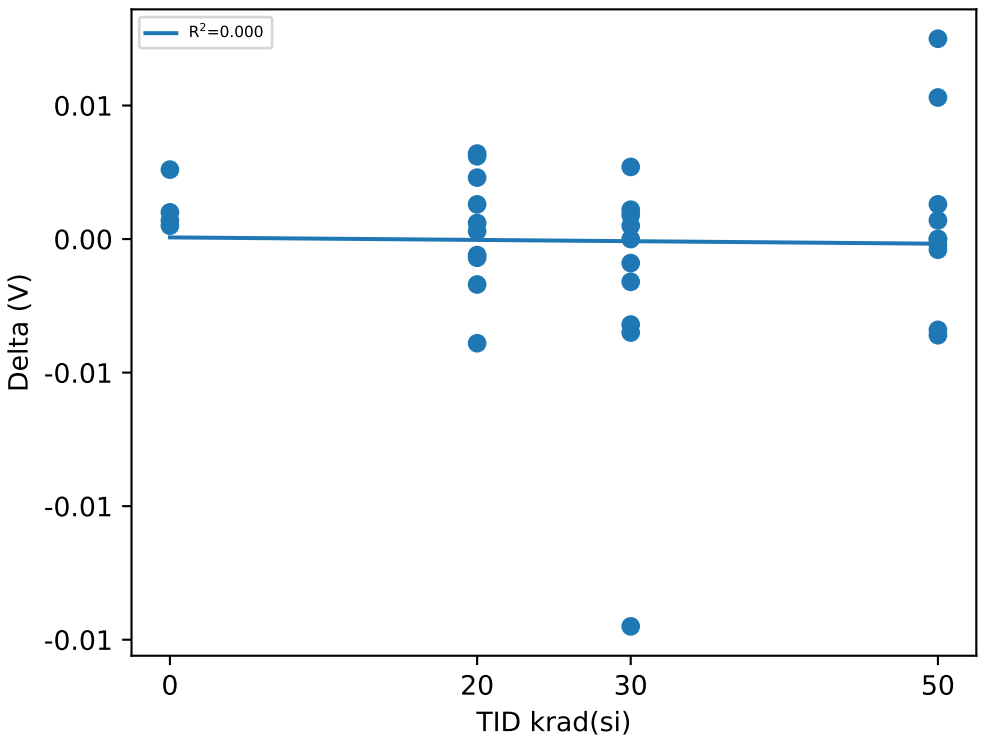
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.4762	5.4872	5.5047	0.0132	5.477	5.4886	5.5055	0.013397	-0.0009	0.001325	0.0029	0.0017405
20	5.4658	5.4797	5.4996	0.0096331	5.4648	5.4801	5.5005	0.010397	-0.0049	0.0004	0.0041	0.0026944
30	5.4715	5.4846	5.5002	0.010085	5.4722	5.4822	5.4967	0.0088005	-0.0188	-0.00235	0.0029	0.0063216
50	5.4606	5.481	5.504	0.011568	5.4593	5.4818	5.5132	0.014254	-0.0045	0.00081	0.0092	0.0041404

Device Test: 15.4 VLDO|V_VLDO/VLDO/12/12/0/0/4.5/500kHz//@V_LDO_4P5

TID vs Result Stats



TID vs Post - Pre Exposure Delta



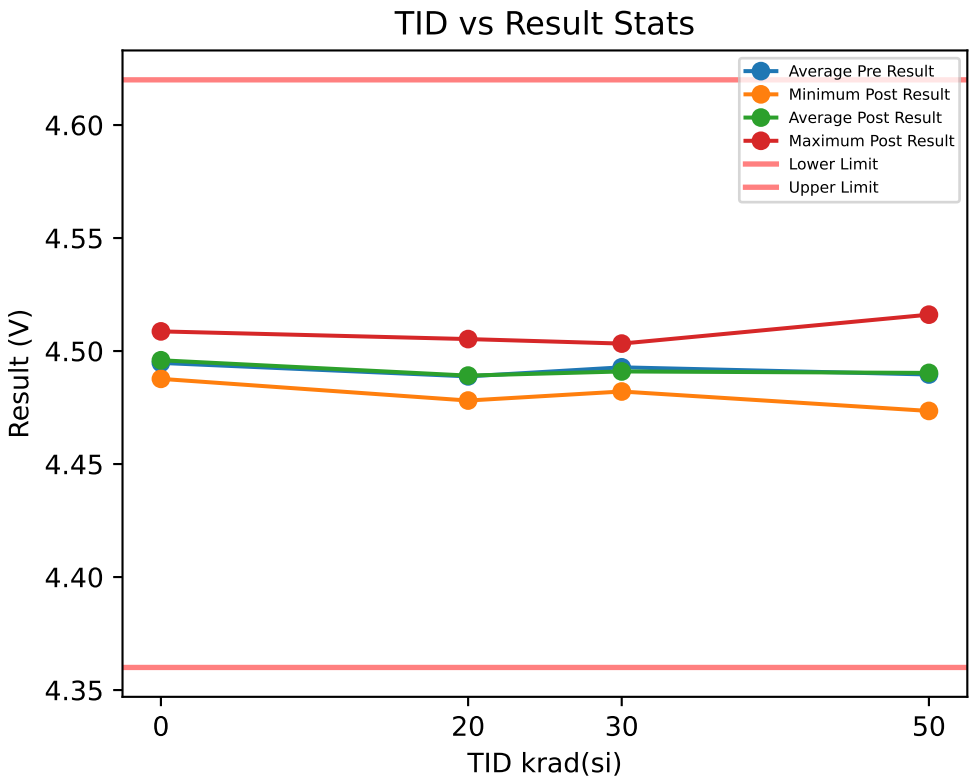
Test Results (Lower Limit = 4.36, Upper Limit = 4.62 (V))

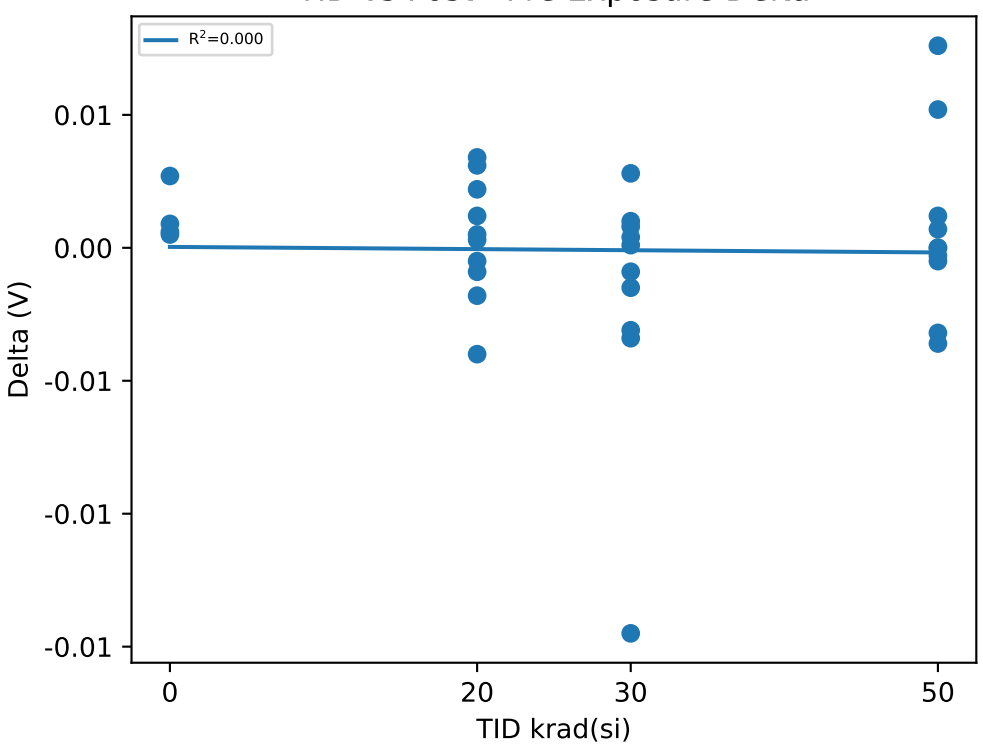
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	4.489	4.4886	-0.0004
2	20	Unbiased	4.4924	4.4907	-0.0017
3	50	Biased	4.5008	4.4972	-0.0036
4	30	Unbiased	4.4877	4.4868	-0.0009
5	50	Unbiased	4.4721	4.4734	0.0013
6	30	Biased	4.488	4.4864	-0.0016
7	50	Biased	4.4926	4.4924	-0.0002
8	30	Unbiased	4.485	4.4818	-0.0032
9	20	Unbiased	4.478	4.4793	0.0013
10	50	Biased	4.4832	4.4832	0
11	30	Biased	4.4927	4.4936	0.0009
12	0	Correlation	4.4867	4.4877	0.001
13	0	Correlation	4.5078	4.5085	0.0007
14	50	Unbiased	4.4849	4.4815	-0.0034
15	20	Biased	4.4786	4.4779	-0.0007
16	20	Unbiased	4.492	4.4952	0.0032
17	20	Biased	4.4862	4.4893	0.0031
18	20	Unbiased	4.4847	4.4808	-0.0039
19	20	Biased	4.4887	4.489	0.0003
20	50	Unbiased	4.5083	4.5158	0.0075
21	0	Correlation	4.4847	4.4873	0.0026
22	50	Unbiased	4.4889	4.4896	0.0007
23	0	Correlation	4.4986	4.4991	0.0005
24	20	Biased	4.5045	4.5051	0.0006
26	50	Biased	4.4841	4.4894	0.0053
27	30	Unbiased	4.4833	4.4833	0
28	30	Biased	4.5048	4.5013	-0.0035
29	30	Unbiased	4.4939	4.495	0.0011
30	20	Biased	4.4856	4.4879	0.0023
31	30	Unbiased	4.4872	4.4877	0.0005
33	30	Biased	4.5002	4.5029	0.0027
34	50	Unbiased	4.4898	4.4898	0
35	20	Unbiased	4.494	4.4934	-0.0006
41	30	Biased	4.5025	4.488	-0.0145

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.4847	4.4944	4.5078	0.01081	4.4873	4.4957	4.5085	0.010164	0.0005	0.0012	0.0026	0.00095568
20	4.478	4.4885	4.5045	0.0078184	4.4779	4.4889	4.5051	0.0082026	-0.0039	0.00039	0.0032	0.0022288
30	4.4833	4.4925	4.5048	0.0076365	4.4818	4.4907	4.5029	0.0072423	-0.0145	-0.00185	0.0027	0.004847
50	4.4721	4.4894	4.5083	0.0099109	4.4734	4.4901	4.5158	0.011154	-0.0036	0.00072	0.0075	0.0034328

Device Test: 15.5 VLDO|V_VLDO/VLDO/14/14/0/0/4.5/500kHz//@V_LDO_4P5





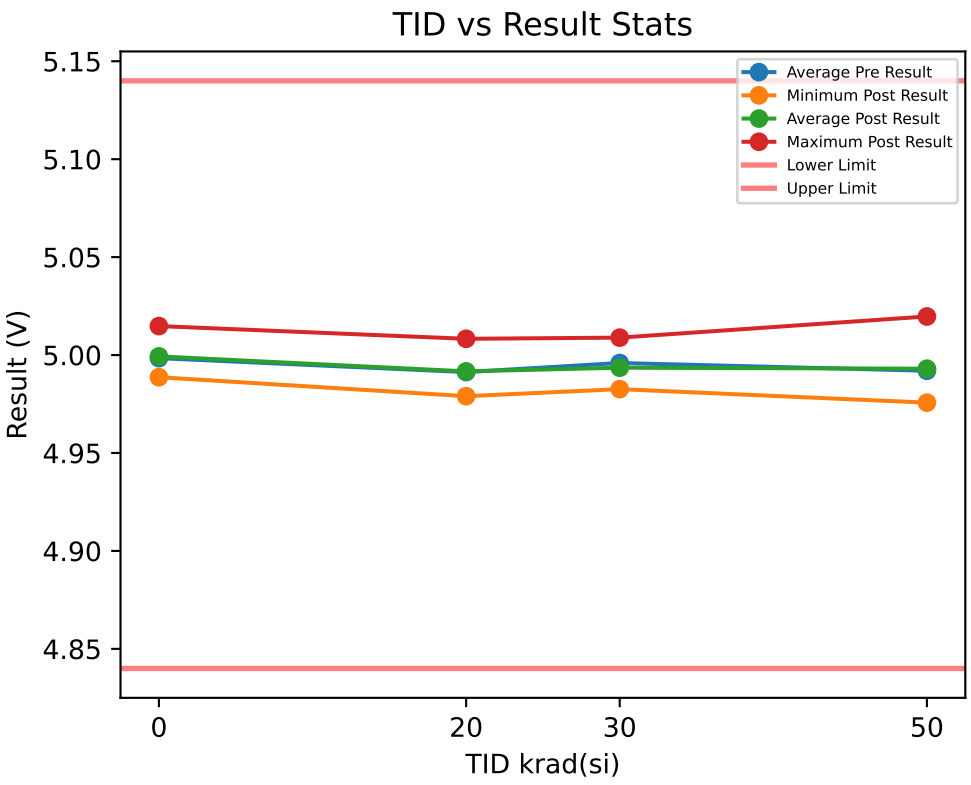
Test Results (Lower Limit = 4.36, Upper Limit = 4.62 (V))

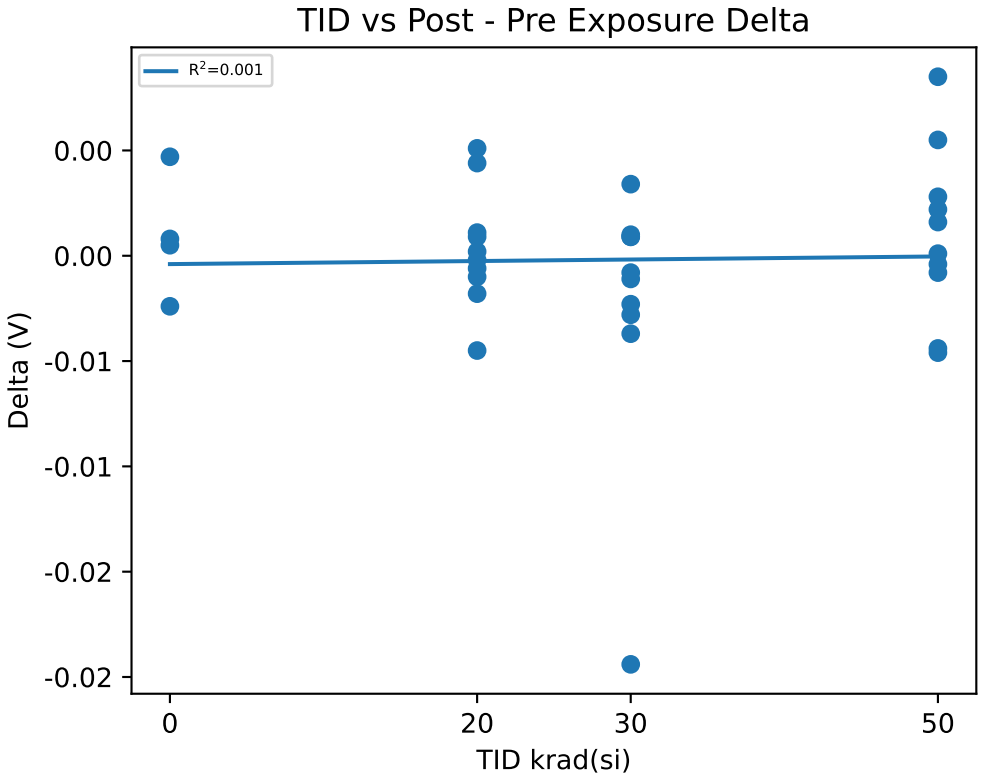
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	4.4893	4.4888	-0.0005
2	20	Unbiased	4.4928	4.491	-0.0018
3	50	Biased	4.501	4.4974	-0.0036
4	30	Unbiased	4.488	4.4871	-0.0009
5	50	Unbiased	4.4723	4.4735	0.0012
6	30	Biased	4.4882	4.4867	-0.0015
7	50	Biased	4.4929	4.4926	-0.0003
8	30	Unbiased	4.4852	4.4821	-0.0031
9	20	Unbiased	4.4784	4.4796	0.0012
10	50	Biased	4.4835	4.4835	0
11	30	Biased	4.493	4.4938	0.0008
12	0	Correlation	4.487	4.4879	0.0009
13	0	Correlation	4.5081	4.5087	0.0006
14	50	Unbiased	4.4851	4.4819	-0.0032
15	20	Biased	4.479	4.4781	-0.0009
16	20	Unbiased	4.4922	4.4956	0.0034
17	20	Biased	4.4864	4.4895	0.0031
18	20	Unbiased	4.485	4.481	-0.004
19	20	Biased	4.489	4.4893	0.0003
20	50	Unbiased	4.5085	4.5161	0.0076
21	0	Correlation	4.485	4.4877	0.0027
22	50	Unbiased	4.4891	4.4898	0.0007
23	0	Correlation	4.4989	4.4994	0.0005
24	20	Biased	4.5048	4.5053	0.0005
26	50	Biased	4.4844	4.4896	0.0052
27	30	Unbiased	4.4836	4.4837	0.0001
28	30	Biased	4.5051	4.5017	-0.0034
29	30	Unbiased	4.4942	4.4952	0.001
30	20	Biased	4.4859	4.4881	0.0022
31	30	Unbiased	4.4875	4.4879	0.0004
33	30	Biased	4.5005	4.5033	0.0028
34	50	Unbiased	4.4901	4.4901	0
35	20	Unbiased	4.4944	4.4939	-0.0005
41	30	Biased	4.5027	4.4882	-0.0145

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.485	4.4947	4.5081	0.01081	4.4877	4.4959	4.5087	0.010121	0.0005	0.001175	0.0027	0.0010308
20	4.4784	4.4888	4.5048	0.0078015	4.4781	4.4891	4.5053	0.0082286	-0.004	0.00035	0.0034	0.0022819
30	4.4836	4.4928	4.5051	0.0076397	4.4821	4.491	4.5033	0.0072641	-0.0145	-0.00183	0.0028	0.0048378
50	4.4723	4.4896	4.5085	0.0099019	4.4735	4.4903	4.5161	0.011172	-0.0036	0.00071	0.0076	0.0034194

Device Test: 15.8 VLDO|V_VLDO/VLDO/5.5/5.5/0/0/5/500kHz//@V_LDO_5





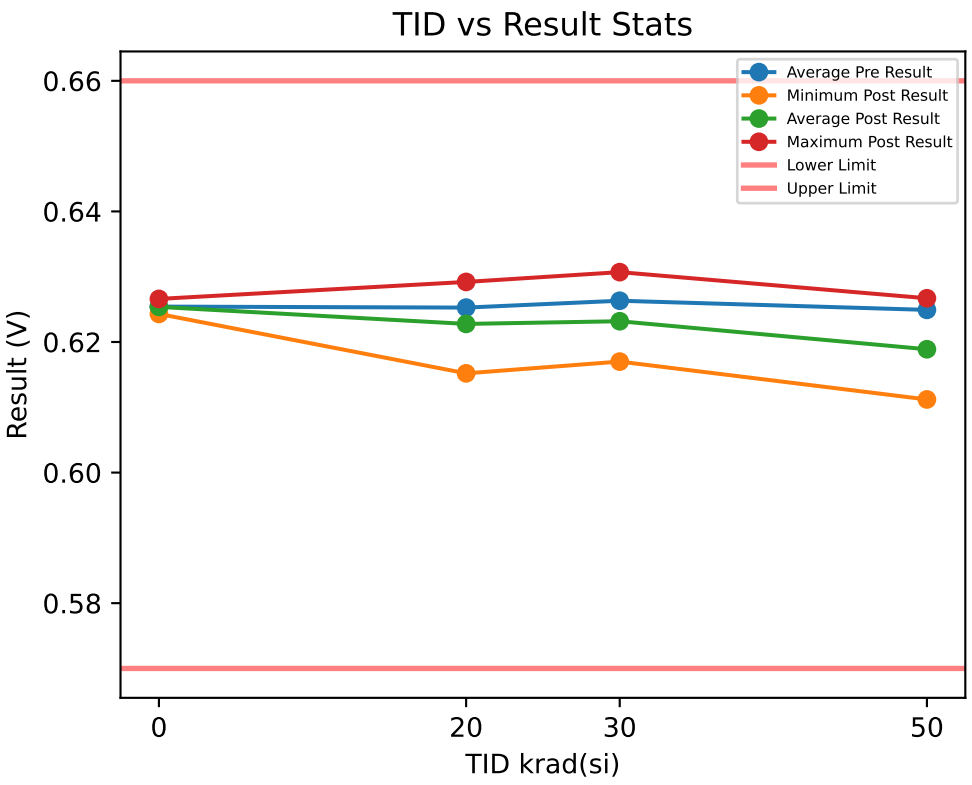
Test Results (Lower Limit = 4.84, Upper Limit = 5.14 (V))

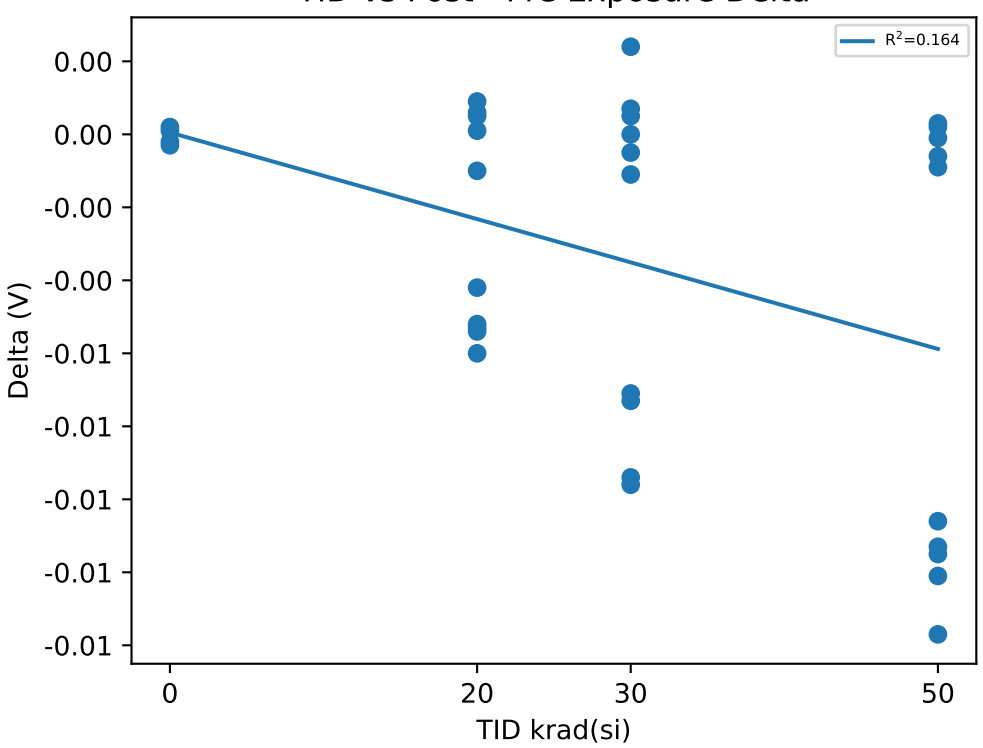
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	4.9929	4.9925	-0.0004
2	20	Unbiased	4.9946	4.9948	0.0002
3	50	Biased	5.0065	5.0021	-0.0044
4	30	Unbiased	4.9884	4.9873	-0.0011
5	50	Unbiased	4.9741	4.9757	0.0016
6	30	Biased	4.9896	4.9906	0.001
7	50	Biased	4.9976	4.9968	-0.0008
8	30	Unbiased	4.9854	4.9826	-0.0028
9	20	Unbiased	4.9808	4.979	-0.0018
10	50	Biased	4.9841	4.9869	0.0028
11	30	Biased	4.9976	4.9985	0.0009
12	0	Correlation	4.9873	4.992	0.0047
13	0	Correlation	5.014	5.0148	0.0008
14	50	Unbiased	4.986	4.9814	-0.0046
15	20	Biased	4.9819	4.9809	-0.001
16	20	Unbiased	4.9932	4.9976	0.0044
17	20	Biased	4.9899	4.9908	0.0009
18	20	Unbiased	4.9861	4.9816	-0.0045
19	20	Biased	4.9931	4.9929	-0.0002
20	50	Unbiased	5.0112	5.0197	0.0085
21	0	Correlation	4.9882	4.9887	0.0005
22	50	Unbiased	4.9905	4.9906	0.0001
23	0	Correlation	5.0042	5.0018	-0.0024
24	20	Biased	5.0072	5.0083	0.0011
26	50	Biased	4.9854	4.9909	0.0055
27	30	Unbiased	4.9872	4.9835	-0.0037
28	30	Biased	5.0077	5.0069	-0.0008
29	30	Unbiased	4.9986	4.9995	0.0009
30	20	Biased	4.9871	4.9922	0.0051
31	30	Unbiased	4.9915	4.9892	-0.0023
33	30	Biased	5.0055	5.0089	0.0034
34	50	Unbiased	4.9916	4.9938	0.0022
35	20	Unbiased	4.9992	4.9986	-0.0006
41	30	Biased	5.0079	4.9885	-0.0194

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9873	4.9984	5.014	0.012965	4.9887	4.9993	5.0148	0.011721	-0.0024	0.0009	0.0047	0.0029155
20	4.9808	4.9913	5.0072	0.0080153	4.979	4.9917	5.0083	0.0091288	-0.0045	0.00036	0.0051	0.0028092
30	4.9854	4.9959	5.0079	0.0087356	4.9826	4.9935	5.0089	0.0093503	-0.0194	-0.00239	0.0034	0.0063429
50	4.9741	4.992	5.0112	0.010933	4.9757	4.993	5.0197	0.011983	-0.0046	0.00105	0.0085	0.0040558

Device Test: 16.1 LEVEL|EN_RISE/EN/4.5/4.5/0/0/4.5/500kHz//@V_EN_RISE





Test Results (Lower Limit = 0.57, Upper Limit = 0.66 (V))

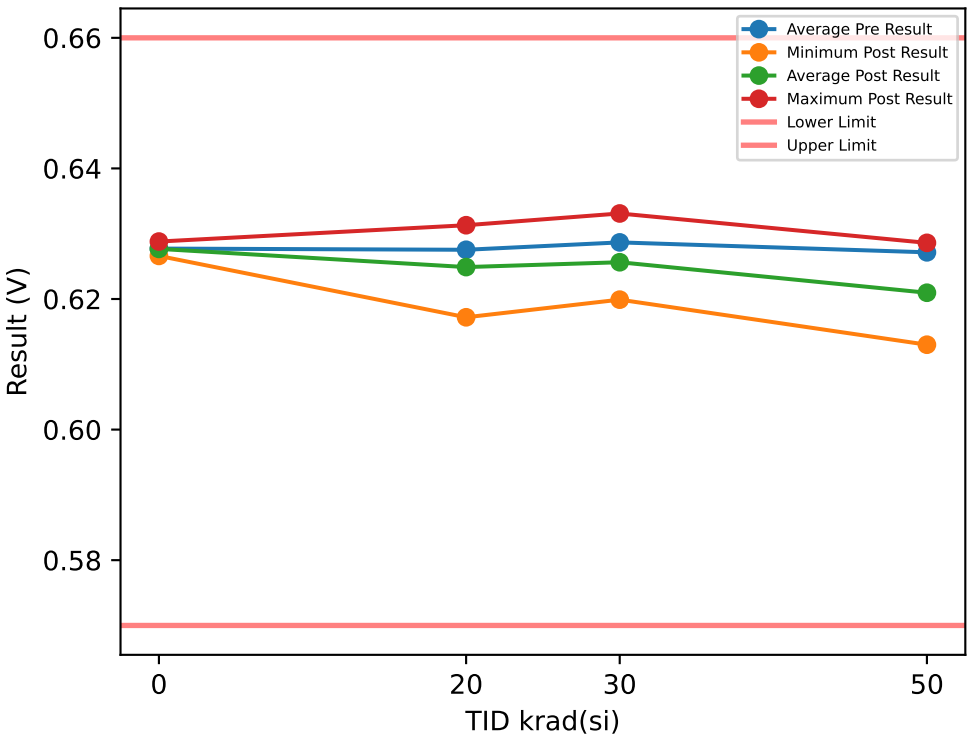
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	0.6268	0.6131	-0.0137
2	20	Unbiased	0.6245	0.6254	0.0009
3	50	Biased	0.6218	0.6112	-0.0106
4	30	Unbiased	0.6231	0.622	-0.0011
5	50	Unbiased	0.6273	0.6267	-0.0006
6	30	Biased	0.6251	0.618	-0.0071
7	50	Biased	0.6238	0.6125	-0.0113
8	30	Unbiased	0.628	0.628	0
9	20	Unbiased	0.6259	0.626	0.0001
10	50	Biased	0.6252	0.6131	-0.0121
11	30	Biased	0.6258	0.6185	-0.0073
12	0	Correlation	0.6246	0.6243	-0.0003
13	0	Correlation	0.6268	0.6266	-0.0002
14	50	Unbiased	0.6235	0.6226	-0.0009
15	20	Biased	0.626	0.62	-0.006
16	20	Unbiased	0.6286	0.6292	0.0006
17	20	Biased	0.6205	0.6152	-0.0053
18	20	Unbiased	0.6241	0.6231	-0.001
19	20	Biased	0.6227	0.6185	-0.0042
20	50	Unbiased	0.6254	0.6253	-0.0001
21	0	Correlation	0.6251	0.6252	0.0001
22	50	Unbiased	0.6231	0.6233	0.0002
23	0	Correlation	0.6252	0.6254	0.0002
24	20	Biased	0.6299	0.6245	-0.0054
26	50	Biased	0.628	0.6165	-0.0115
27	30	Unbiased	0.63	0.6307	0.0007
28	30	Biased	0.6266	0.617	-0.0096
29	30	Unbiased	0.626	0.6265	0.0005
30	20	Biased	0.6252	0.62	-0.0052
31	30	Unbiased	0.6231	0.6226	-0.0005
33	30	Biased	0.6279	0.6185	-0.0094
34	50	Unbiased	0.6243	0.6246	0.0003
35	20	Unbiased	0.6253	0.6258	0.0005
41	30	Biased	0.6276	0.63	0.0024

Test Statistics (V)

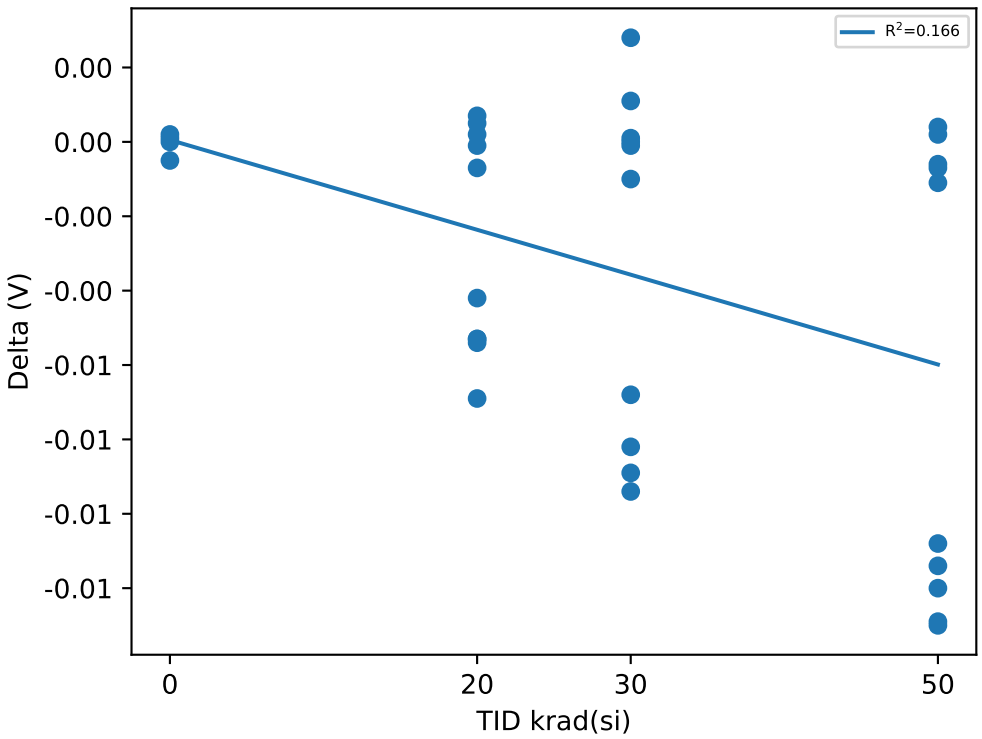
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.6246	0.62543	0.6268	0.0009535	0.6243	0.62538	0.6266	0.00094648	-0.0003	-5e-05	0.0002	0.00023805
20	0.6205	0.62527	0.6299	0.0026829	0.6152	0.62277	0.6292	0.0042408	-0.006	-0.0025	0.0009	0.0029413
30	0.6231	0.62632	0.63	0.0021903	0.617	0.62318	0.6307	0.005248	-0.0096	-0.00314	0.0024	0.0046378
50	0.6218	0.62492	0.628	0.0019915	0.6112	0.61889	0.6267	0.006152	-0.0137	-0.00603	0.0003	0.0061833

Device Test: 16.10 LEVEL|EN_RISE/EN/14/14/0/0/5/500kHz//@V_EN_RISE

TID vs Result Stats



TID vs Post - Pre Exposure Delta



Test Results (Lower Limit = 0.57, Upper Limit = 0.66 (V))

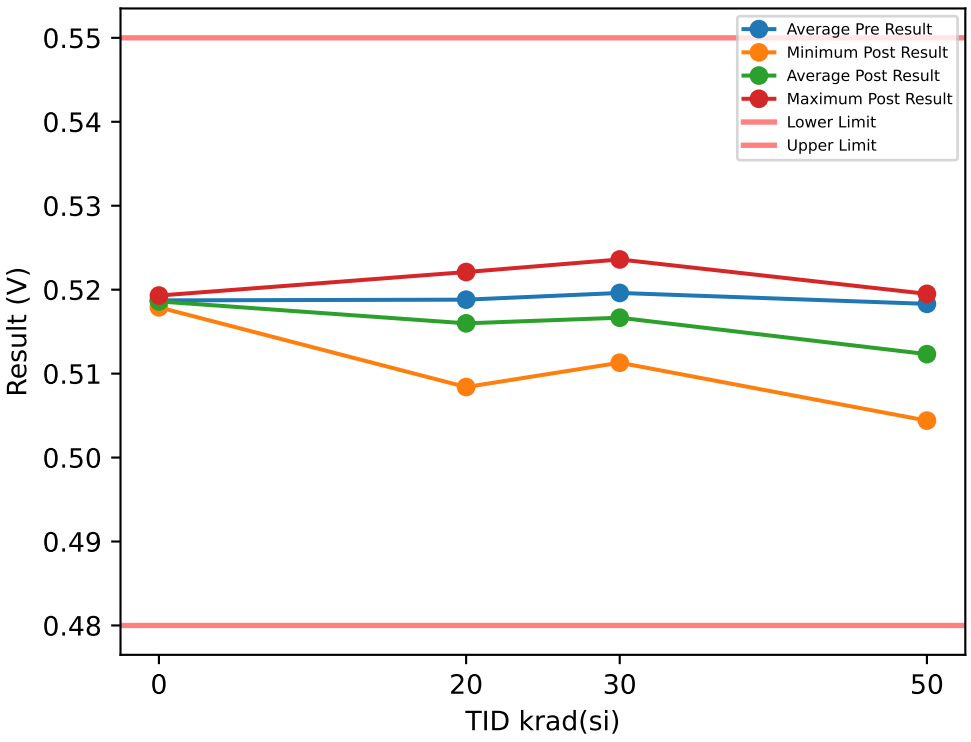
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	0.6288	0.6159	-0.0129
2	20	Unbiased	0.6268	0.6273	0.0005
3	50	Biased	0.6238	0.613	-0.0108
4	30	Unbiased	0.6251	0.6241	-0.001
5	50	Unbiased	0.6293	0.6286	-0.0007
6	30	Biased	0.6273	0.6205	-0.0068
7	50	Biased	0.6258	0.6144	-0.0114
8	30	Unbiased	0.6306	0.6306	0
9	20	Unbiased	0.6279	0.6281	0.0002
10	50	Biased	0.6275	0.6145	-0.013
11	30	Biased	0.6287	0.6205	-0.0082
12	0	Correlation	0.6271	0.6266	-0.0005
13	0	Correlation	0.6286	0.6288	0.0002
14	50	Unbiased	0.6256	0.6245	-0.0011
15	20	Biased	0.6287	0.6218	-0.0069
16	20	Unbiased	0.6314	0.6313	-0.0001
17	20	Biased	0.6225	0.6172	-0.0053
18	20	Unbiased	0.6258	0.6251	-0.0007
19	20	Biased	0.6246	0.6204	-0.0042
20	50	Unbiased	0.6279	0.6281	0.0002
21	0	Correlation	0.6279	0.6279	0
22	50	Unbiased	0.6251	0.6255	0.0004
23	0	Correlation	0.6273	0.6274	0.0001
24	20	Biased	0.6319	0.6265	-0.0054
26	50	Biased	0.6305	0.6185	-0.012
27	30	Unbiased	0.632	0.6331	0.0011
28	30	Biased	0.6293	0.6199	-0.0094
29	30	Unbiased	0.6285	0.6286	0.0001
30	20	Biased	0.6278	0.6225	-0.0053
31	30	Unbiased	0.6253	0.6252	-0.0001
33	30	Biased	0.63	0.6211	-0.0089
34	50	Unbiased	0.6272	0.6266	-0.0006
35	20	Unbiased	0.628	0.6287	0.0007
41	30	Biased	0.6299	0.6327	0.0028

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.6271	0.62772	0.6286	0.00067515	0.6266	0.62767	0.6288	0.0009215	-0.0005	-5e-05	0.0002	0.00031091
20	0.6225	0.62754	0.6319	0.0028535	0.6172	0.62489	0.6313	0.0043322	-0.0069	-0.00265	0.0007	0.0030119
30	0.6251	0.62867	0.632	0.0022236	0.6199	0.62563	0.6331	0.0052474	-0.0094	-0.00304	0.0028	0.0046987
50	0.6238	0.62715	0.6305	0.0020791	0.613	0.62096	0.6286	0.0062724	-0.013	-0.00619	0.0004	0.0061924

Device Test: 16.11 LEVEL|EN_FALL/EN/14/14/0/0/5/500kHz//@V_EN_FALL

TID vs Result Stats



TID vs Post - Pre Exposure Delta

Test Results (Lower Limit = 0.48, Upper Limit = 0.55 (V))

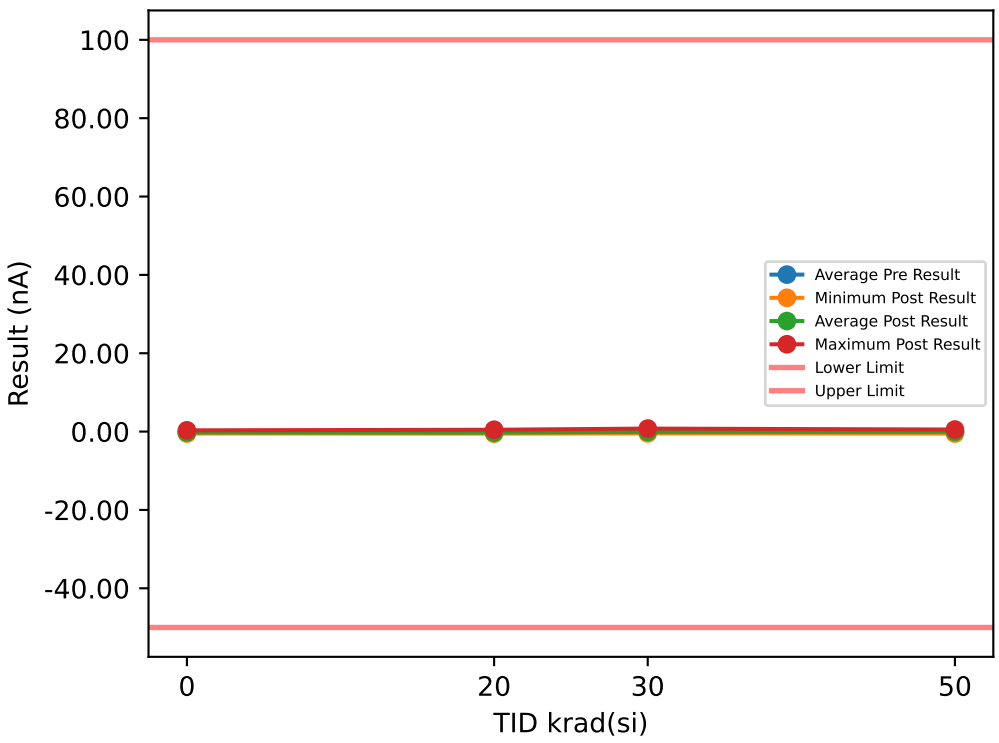
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	0.5194	0.5061	-0.0133
2	20	Unbiased	0.5179	0.5187	0.0008
3	50	Biased	0.5152	0.5044	-0.0108
4	30	Unbiased	0.5166	0.5158	-0.0008
5	50	Unbiased	0.52	0.5195	-0.0005
6	30	Biased	0.518	0.5113	-0.0067
7	50	Biased	0.518	0.5066	-0.0114
8	30	Unbiased	0.5221	0.5214	-0.0007
9	20	Unbiased	0.5193	0.5194	0.0001
10	50	Biased	0.5189	0.5066	-0.0123
11	30	Biased	0.5194	0.5122	-0.0072
12	0	Correlation	0.518	0.5179	-0.0001
13	0	Correlation	0.5193	0.5193	0
14	50	Unbiased	0.5168	0.516	-0.0008
15	20	Biased	0.52	0.5134	-0.0066
16	20	Unbiased	0.5221	0.5221	0
17	20	Biased	0.5139	0.5084	-0.0055
18	20	Unbiased	0.5174	0.5166	-0.0008
19	20	Biased	0.516	0.5113	-0.0047
20	50	Unbiased	0.5187	0.5194	0.0007
21	0	Correlation	0.5188	0.5186	-0.0002
22	50	Unbiased	0.5163	0.5175	0.0012
23	0	Correlation	0.5188	0.5186	-0.0002
24	20	Biased	0.5234	0.5173	-0.0061
26	50	Biased	0.5219	0.5099	-0.012
27	30	Unbiased	0.5228	0.5236	0.0008
28	30	Biased	0.521	0.5113	-0.0097
29	30	Unbiased	0.5194	0.5193	-0.0001
30	20	Biased	0.5193	0.514	-0.0053
31	30	Unbiased	0.516	0.5161	0.0001
33	30	Biased	0.5207	0.512	-0.0087
34	50	Unbiased	0.5179	0.5172	-0.0007
35	20	Unbiased	0.5188	0.5187	-0.0001
41	30	Biased	0.5201	0.5236	0.0035

Test Statistics (V)

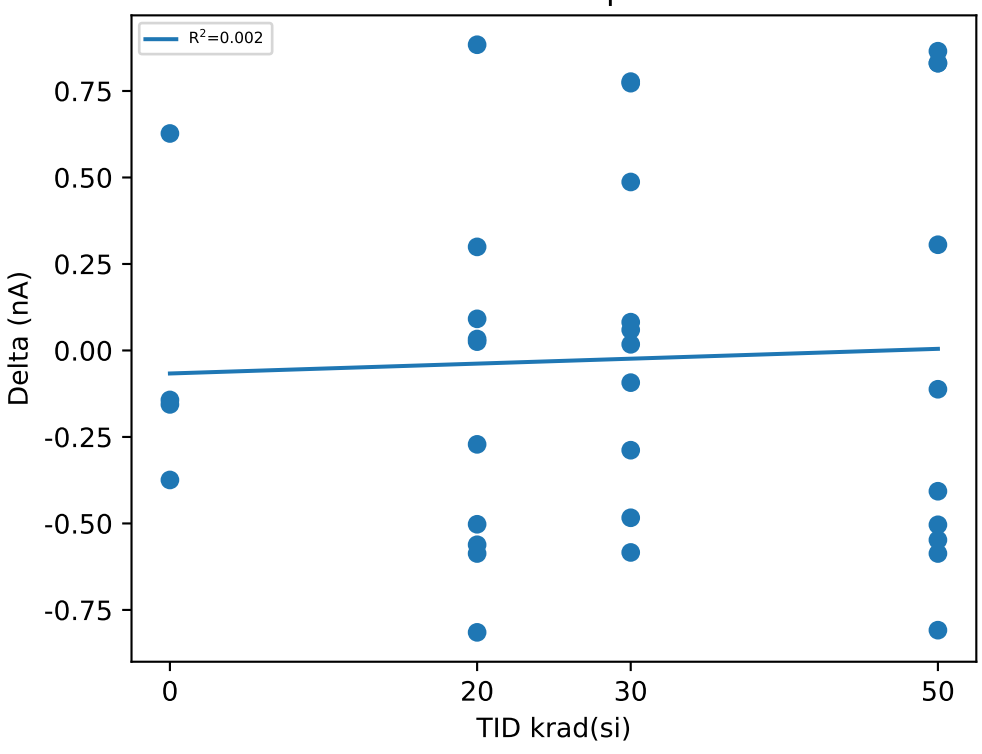
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.518	0.51872	0.5193	0.00053774	0.5179	0.5186	0.5193	0.00057155	-0.0002	-0.000125	0	9.5743e-05
20	0.5139	0.51881	0.5234	0.002761	0.5084	0.51599	0.5221	0.0041635	-0.0066	-0.00282	0.0008	0.0030364
30	0.516	0.51961	0.5228	0.0022238	0.5113	0.51666	0.5236	0.0050098	-0.0097	-0.00295	0.0035	0.0046371
50	0.5152	0.51831	0.5219	0.0019347	0.5044	0.51232	0.5195	0.0061335	-0.0133	-0.00599	0.0012	0.0063534

Device Test: 16.15 LEAK|EN_LEAK/EN/14/14/0/0/5/500kHz//@I_EN_LEAK_1V

TID vs Result Stats



TID vs Post - Pre Exposure Delta



Test Results (Lower Limit = -50.0, Upper Limit = 100.0 (nA))

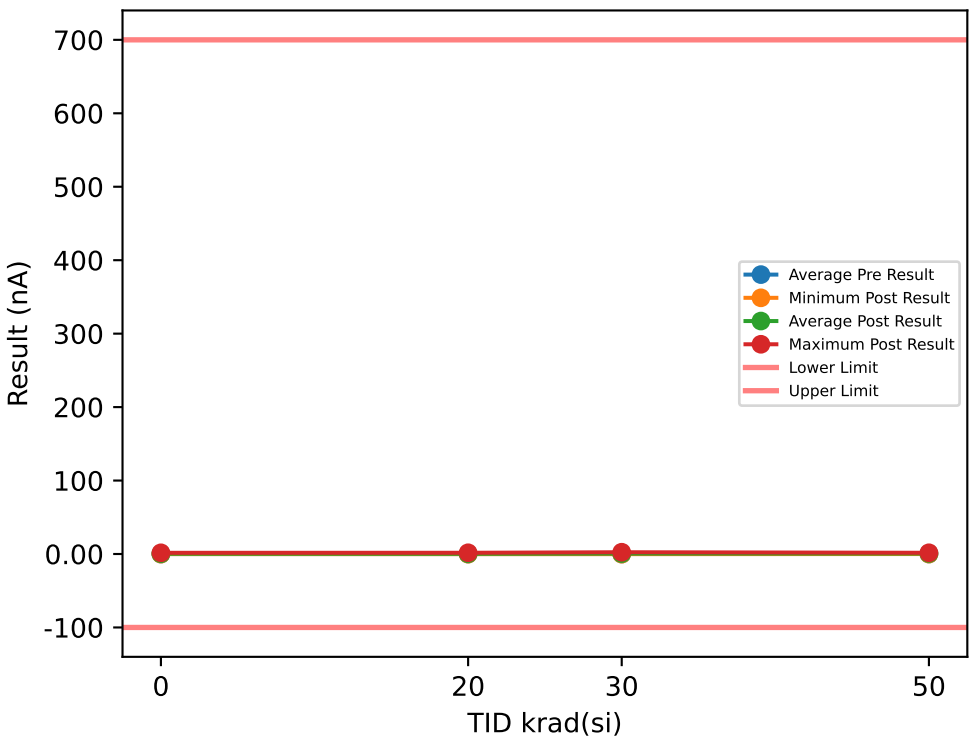
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	-0.305	0.5254	0.8304
2	20	Unbiased	0.1635	0.4629	0.2994
3	50	Biased	-0.424	0.441	0.865
4	30	Unbiased	0.0259	-0.2624	-0.2883
5	50	Unbiased	-0.3518	-0.4639	-0.1121
6	30	Biased	0.1729	-0.4109	-0.5838
7	50	Biased	-0.4646	0.366	0.8306
8	30	Unbiased	0.0477	-0.4359	-0.4836
9	20	Unbiased	-0.2612	-0.2281	0.0331
10	50	Biased	0.2072	-0.3797	-0.5869
11	30	Biased	-0.4365	-0.3547	0.0818
12	0	Correlation	0.0633	-0.311	-0.3743
13	0	Correlation	-0.305	0.3222	0.6272
14	50	Unbiased	0.2353	-0.2686	-0.5039
15	20	Biased	-0.3615	-0.336	0.0255
16	20	Unbiased	0.0509	-0.4515	-0.5024
17	20	Biased	-0.2581	-0.5295	-0.2714
18	20	Unbiased	0.329	-0.4858	-0.8148
19	20	Biased	-0.4115	0.4722	0.8837
20	50	Unbiased	0.1601	-0.2468	-0.4069
21	0	Correlation	-0.2612	-0.4171	-0.1559
22	50	Unbiased	0.2759	-0.2718	-0.5477
23	0	Correlation	-0.3459	-0.4889	-0.143
24	20	Biased	0.1039	-0.4577	-0.5616
26	50	Biased	0.3071	-0.5014	-0.8085
27	30	Unbiased	-0.2365	-0.2187	0.0178
28	30	Biased	0.0134	0.5004	0.487
29	30	Unbiased	-0.3674	0.4097	0.7771
30	20	Biased	0.2884	-0.2985	-0.5869
31	30	Unbiased	-0.3678	-0.4608	-0.093
33	30	Biased	-0.383	-0.3235	0.0595
34	50	Unbiased	0.1073	0.4129	0.3056
35	20	Unbiased	-0.6115	-0.5201	0.0914
41	30	Biased	-0.005	0.7676	0.7726

Test Statistics (nA)

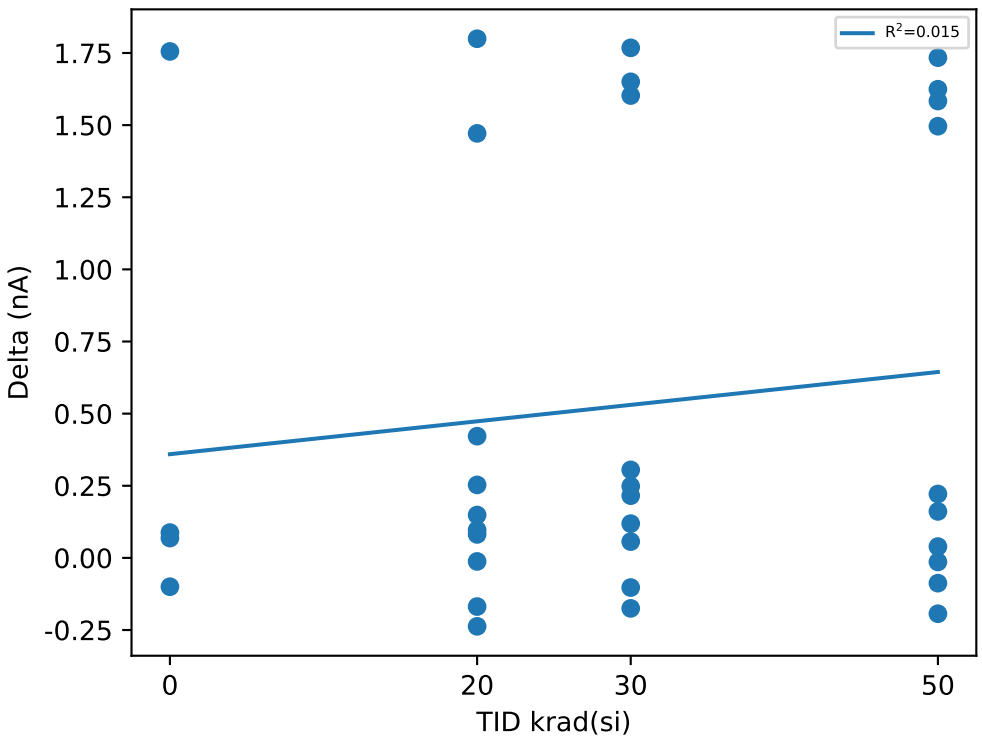
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.3459	-0.2122	0.0633	0.18689	-0.4889	-0.2237	0.3222	0.3712	-0.3743	-0.0115	0.6272	0.43883
20	-0.6115	-0.09681	0.329	0.32431	-0.5295	-0.23721	0.4722	0.38425	-0.8148	-0.1404	0.8837	0.50918
30	-0.4365	-0.15363	0.1729	0.22618	-0.4608	-0.07892	0.7676	0.45504	-0.5838	0.07471	0.7771	0.47833
50	-0.4646	-0.02525	0.3071	0.31831	-0.5014	-0.03869	0.5254	0.41869	-0.8085	-0.01344	0.865	0.66244

Device Test: 16.16 LEAK|EN_LEAK/EN/14/14/0/0/5/500kHz//@I_EN_LEAK

TID vs Result Stats



TID vs Post - Pre Exposure Delta



Test Results (Lower Limit = -100.0, Upper Limit = 700.0 (nA))

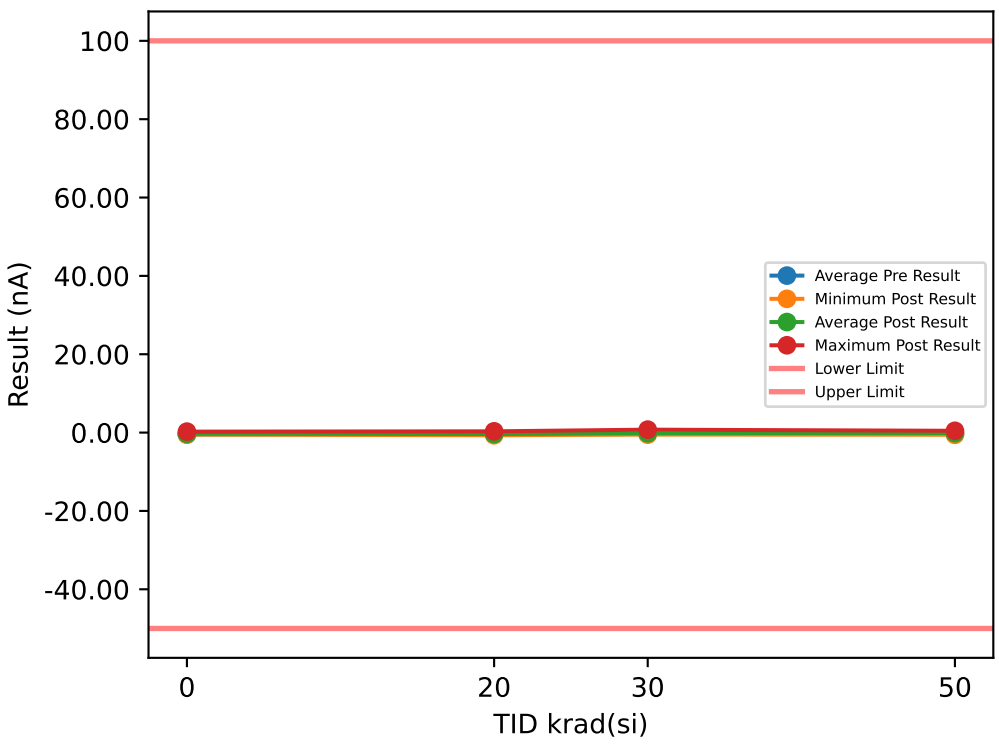
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	-0.1207	1.4628	1.5835
2	20	Unbiased	0.1978	1.6691	1.4713
3	50	Biased	-0.1803	1.5535	1.7338
4	30	Unbiased	-0.1489	0.0997	0.2486
5	50	Unbiased	-0.0832	0.1383	0.2215
6	30	Biased	0.2291	0.0541	-0.175
7	50	Biased	-0.1272	1.4972	1.6244
8	30	Unbiased	-0.0864	-0.1892	-0.1028
9	20	Unbiased	-0.0583	0.0903	0.1486
10	50	Biased	0.2291	0.1415	-0.0876
11	30	Biased	-0.2084	0.0073	0.2157
12	0	Correlation	-0.102	-0.0333	0.0687
13	0	Correlation	-0.1363	1.6191	1.7554
14	50	Unbiased	0.1417	0.1277	-0.014
15	20	Biased	-0.1303	0.1227	0.253
16	20	Unbiased	-0.049	0.0324	0.0814
17	20	Biased	-0.1332	-0.0363	0.0969
18	20	Unbiased	0.1885	-0.0488	-0.2373
19	20	Biased	-0.2334	1.566	1.7994
20	50	Unbiased	-0.1707	-0.0096	0.1611
21	0	Correlation	0.2509	0.151	-0.0999
22	50	Unbiased	0.1666	0.2058	0.0392
23	0	Correlation	-0.2084	-0.1206	0.0878
24	20	Biased	-0.1832	-0.1955	-0.0123
26	50	Biased	0.1323	-0.0613	-0.1936
27	30	Unbiased	-0.2022	0.1028	0.305
28	30	Biased	-0.0365	1.566	1.6025
29	30	Unbiased	-0.1738	1.5941	1.7679
30	20	Biased	0.2228	0.0541	-0.1687
31	30	Unbiased	-0.0772	-0.0207	0.0565
33	30	Biased	-0.1395	-0.0208	0.1187
34	50	Unbiased	0.1573	1.6535	1.4962
35	20	Unbiased	-0.3147	0.1071	0.4218
41	30	Biased	0.7695	2.4196	1.6501

Test Statistics (nA)

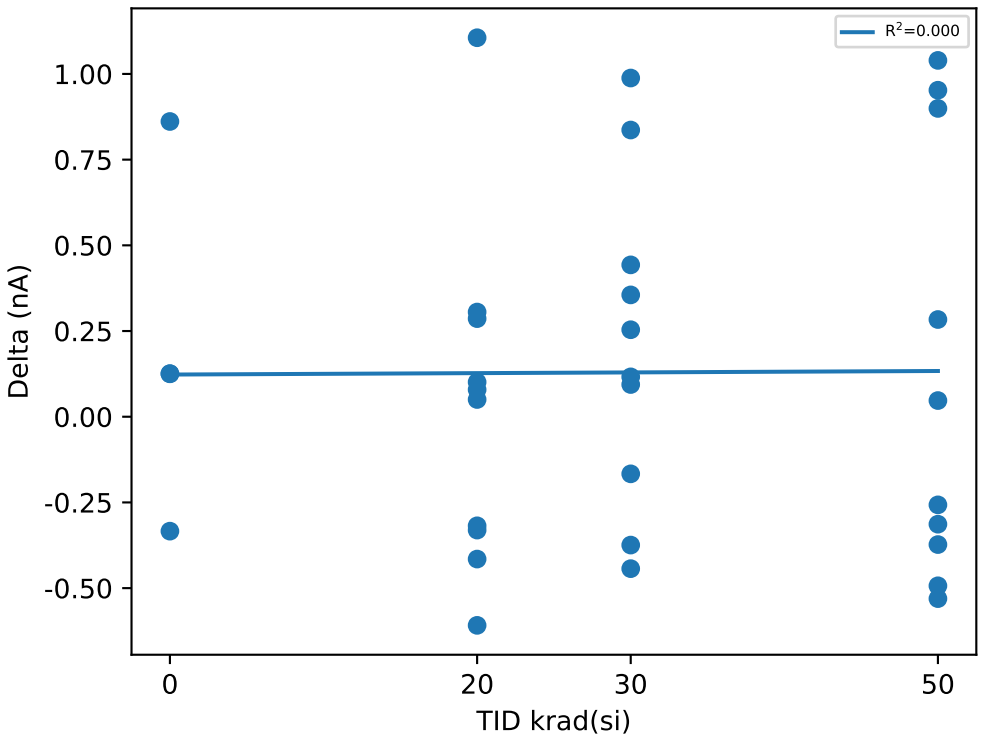
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.2084	-0.04895	0.2509	0.20476	-0.1206	0.40405	1.6191	0.81791	-0.0999	0.453	1.7554	0.87235
20	-0.3147	-0.0493	0.2228	0.19078	-0.1955	0.33611	1.6691	0.68225	-0.2373	0.38541	1.7994	0.68977
30	-0.2084	-0.00743	0.7695	0.30092	-0.1892	0.56129	2.4196	0.92842	-0.175	0.56872	1.7679	0.77758
50	-0.1803	0.01449	0.2291	0.16323	-0.0613	0.67094	1.6535	0.7549	-0.1936	0.65645	1.7338	0.83022

Device Test: 16.17 LEAK|EN_LEAK/EN/14/14/0/1000/5/500kHz//@I_EN_LEAK_1V

TID vs Result Stats



TID vs Post - Pre Exposure Delta



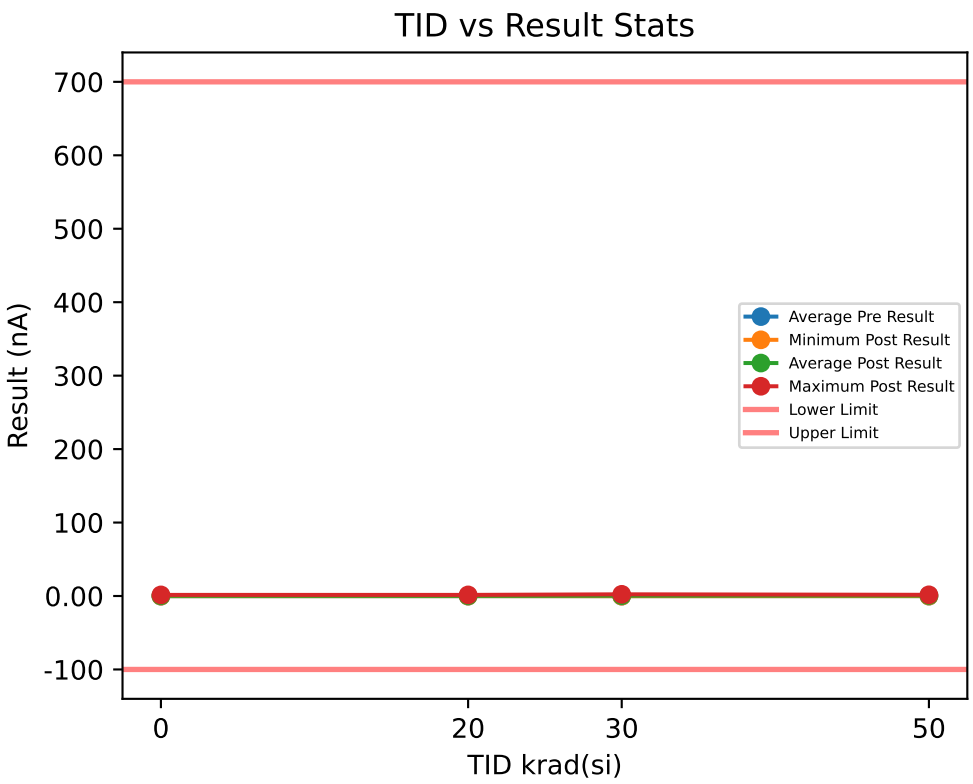
Test Results (Lower Limit = -50.0, Upper Limit = 100.0 (nA))

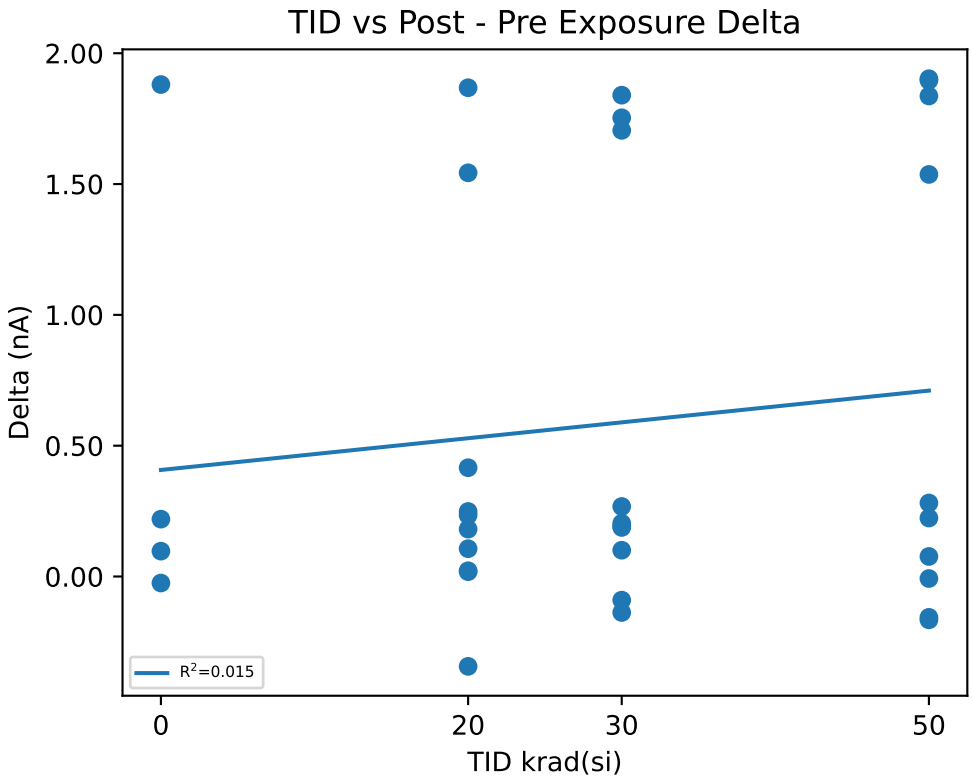
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	-0.5829	0.4566	1.0395
2	20	Unbiased	-0.0207	0.2847	0.3054
3	50	Biased	-0.5896	0.3629	0.9525
4	30	Unbiased	-0.1707	-0.3373	-0.1666
5	50	Unbiased	-0.611	-0.5638	0.0472
6	30	Biased	-0.0269	-0.4701	-0.4432
7	50	Biased	-0.5709	0.3285	0.8994
8	30	Unbiased	-0.1395	-0.5139	-0.3744
9	20	Unbiased	-0.5954	-0.3092	0.2862
10	50	Biased	-0.0207	-0.5513	-0.5306
11	30	Biased	-0.7271	-0.4733	0.2538
12	0	Correlation	-0.1769	-0.5107	-0.3338
13	0	Correlation	-0.6172	0.2441	0.8613
14	50	Unbiased	0.0137	-0.3592	-0.3729
15	20	Biased	-0.6615	-0.5825	0.079
16	20	Unbiased	-0.1676	-0.4858	-0.3182
17	20	Biased	-0.6329	-0.5826	0.0503
18	20	Unbiased	-0.0893	-0.5045	-0.4152
19	20	Biased	-0.7834	0.3222	1.1056
20	50	Unbiased	-0.1832	-0.4403	-0.2571
21	0	Correlation	-0.5642	-0.439	0.1252
22	50	Unbiased	-0.0394	-0.3529	-0.3135
23	0	Correlation	-0.599	-0.4733	0.1257
24	20	Biased	-0.1894	-0.5201	-0.3307
26	50	Biased	-0.0519	-0.5451	-0.4932
27	30	Unbiased	-0.6865	-0.3311	0.3554
28	30	Biased	-0.102	0.341	0.443
29	30	Unbiased	-0.5204	0.316	0.8364
30	20	Biased	0.0355	-0.5731	-0.6086
31	30	Unbiased	-0.5771	-0.4608	0.1163
33	30	Biased	-0.5735	-0.4795	0.094
34	50	Unbiased	0.0605	0.3441	0.2836
35	20	Unbiased	-0.7802	-0.6792	0.101
41	30	Biased	-0.2392	0.7489	0.9881

Test Statistics (nA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.6172	-0.48933	-0.1769	0.20944	-0.5107	-0.29473	0.2441	0.36041	-0.3338	0.1946	0.8613	0.49439
20	-0.7834	-0.38849	0.0355	0.32989	-0.6792	-0.36301	0.3222	0.36396	-0.6086	0.02548	1.1056	0.49028
30	-0.7271	-0.37629	-0.0269	0.26536	-0.5139	-0.16601	0.7489	0.45658	-0.4432	0.21028	0.9881	0.47228
50	-0.611	-0.25754	0.0605	0.29164	-0.5638	-0.13205	0.4566	0.44203	-0.5306	0.12549	1.0395	0.62806

Device Test: 16.18 LEAK|EN_LEAK/EN/14/14/0/1000/5/500kHz//@I_EN_LEAK





Test Results (Lower Limit = -100.0, Upper Limit = 700.0 (nA))

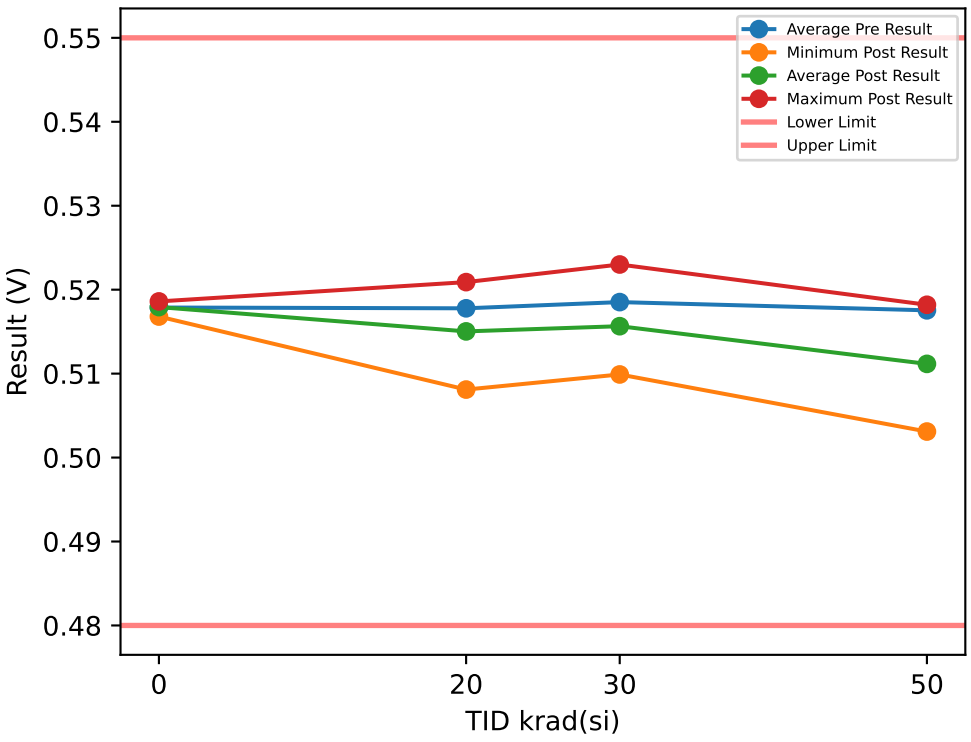
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	-0.358	1.4785	1.8365
2	20	Unbiased	-0.0363	1.5066	1.5429
3	50	Biased	-0.4678	1.4347	1.9025
4	30	Unbiased	-0.2269	-0.0346	0.1923
5	50	Unbiased	-0.2519	0.0291	0.281
6	30	Biased	0.0449	-0.0926	-0.1375
7	50	Biased	-0.274	1.6222	1.8962
8	30	Unbiased	-0.1489	-0.2392	-0.0903
9	20	Unbiased	-0.305	-0.0564	0.2486
10	50	Biased	0.1167	-0.0489	-0.1656
11	30	Biased	-0.3397	-0.1363	0.2034
12	0	Correlation	-0.2706	-0.1737	0.0969
13	0	Correlation	-0.3768	1.5035	1.8803
14	50	Unbiased	-0.0019	-0.0096	-0.0077
15	20	Biased	-0.4584	-0.0426	0.4158
16	20	Unbiased	-0.1582	-0.1362	0.022
17	20	Biased	-0.2831	-0.1768	0.1063
18	20	Unbiased	0.1947	-0.1487	-0.3434
19	20	Biased	-0.3615	1.5066	1.8681
20	50	Unbiased	-0.283	-0.0595	0.2235
21	0	Correlation	0.0729	0.048	-0.0249
22	50	Unbiased	-0.0269	0.0497	0.0766
23	0	Correlation	-0.4334	-0.2142	0.2192
24	20	Biased	-0.3143	-0.1331	0.1812
26	50	Biased	0.0137	-0.1424	-0.1561
27	30	Unbiased	-0.3178	-0.0502	0.2676
28	30	Biased	-0.3049	1.4003	1.7052
29	30	Unbiased	-0.3612	1.4785	1.8397
30	20	Biased	0.0418	0.0603	0.0185
31	30	Unbiased	-0.3178	-0.2173	0.1005
33	30	Biased	-0.3612	-0.1737	0.1875
34	50	Unbiased	0.0074	1.5441	1.5367
35	20	Unbiased	-0.2428	-0.0083	0.2345
41	30	Biased	0.5478	2.3011	1.7533

Test Statistics (nA)

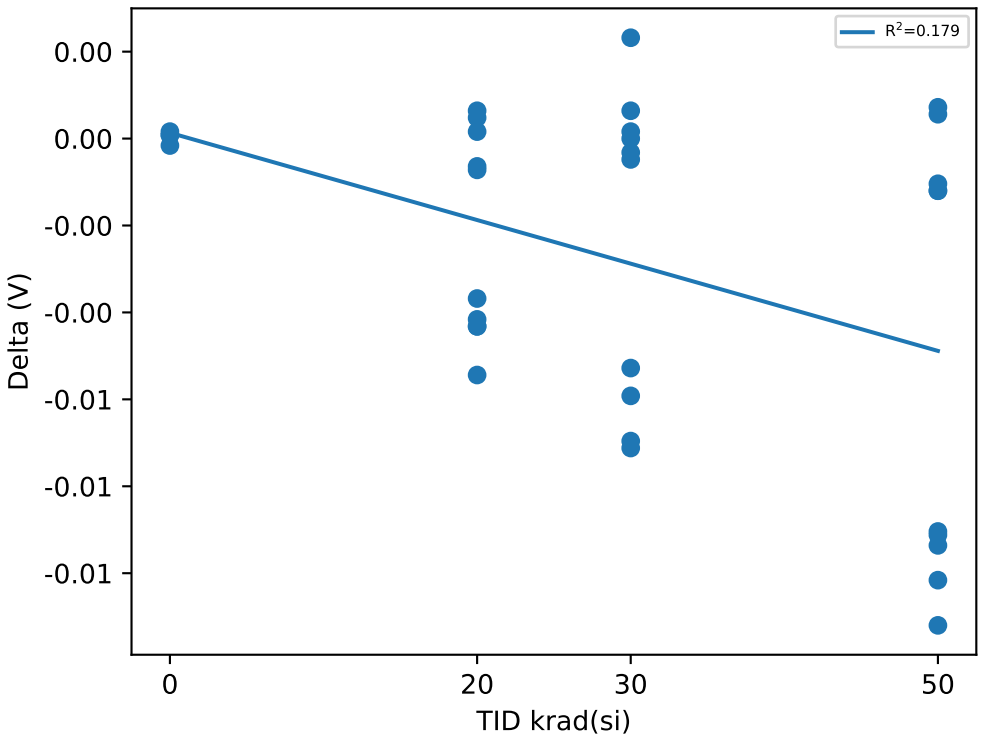
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.4334	-0.25198	0.0729	0.22685	-0.2142	0.2909	1.5035	0.81657	-0.0249	0.54287	1.8803	0.89717
20	-0.4584	-0.19231	0.1947	0.20218	-0.1768	0.23714	1.5066	0.67294	-0.3434	0.42945	1.8681	0.70543
30	-0.3612	-0.17857	0.5478	0.28444	-0.2392	0.4236	2.3011	0.93172	-0.1375	0.60217	1.8397	0.81394
50	-0.4678	-0.15257	0.1167	0.19648	-0.1424	0.58979	1.6222	0.80355	-0.1656	0.74236	1.9025	0.92044

Device Test: 16.2 LEVEL|EN_FALL/EN/4.5/4.5/0/0/4.5/500kHz//@V_EN_FALL

TID vs Result Stats



TID vs Post - Pre Exposure Delta



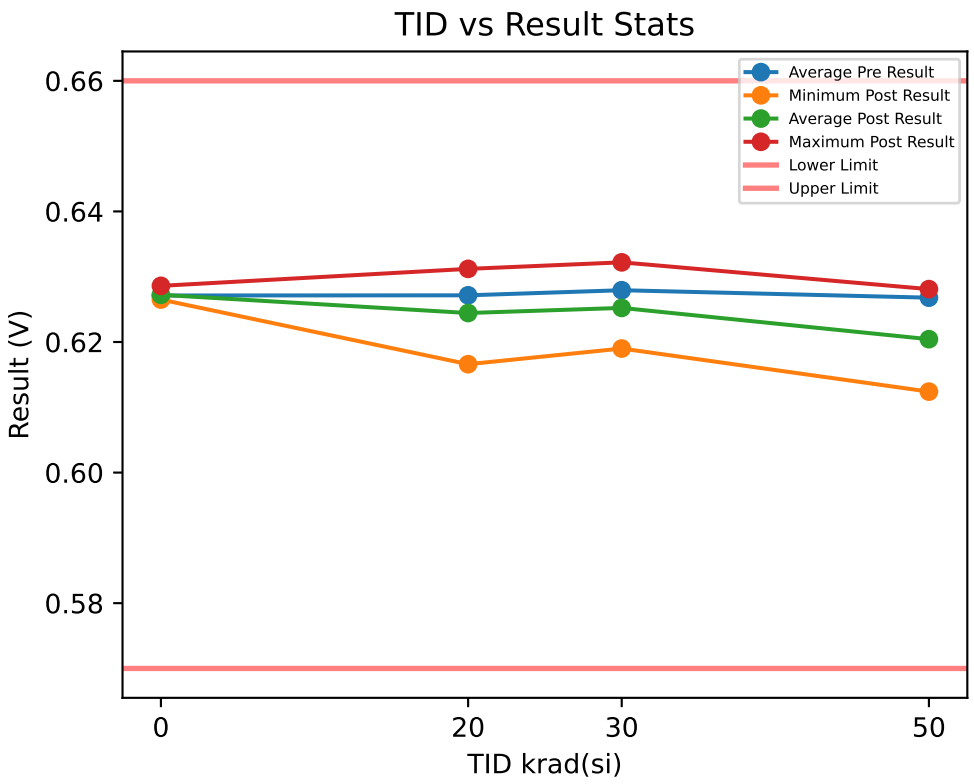
Test Results (Lower Limit = 0.48, Upper Limit = 0.55 (V))

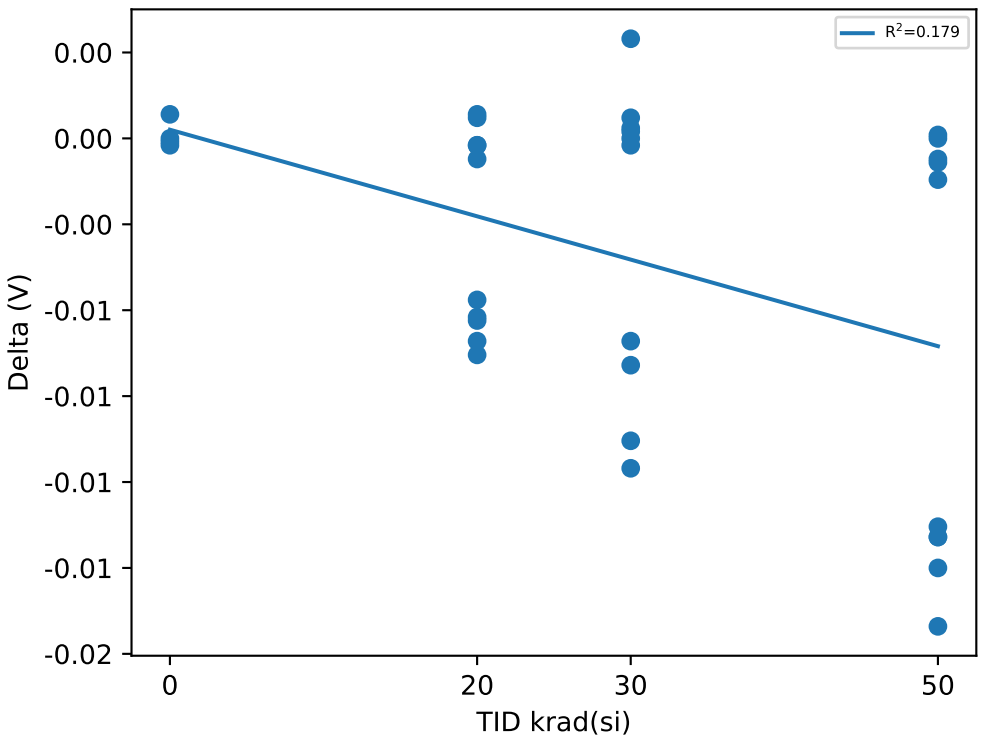
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	0.5193	0.5053	-0.014
2	20	Unbiased	0.5173	0.5181	0.0008
3	50	Biased	0.5148	0.5031	-0.0117
4	30	Unbiased	0.5154	0.515	-0.0004
5	50	Unbiased	0.5194	0.5179	-0.0015
6	30	Biased	0.5165	0.5099	-0.0066
7	50	Biased	0.5167	0.5054	-0.0113
8	30	Unbiased	0.5207	0.5209	0.0002
9	20	Unbiased	0.5188	0.518	-0.0008
10	50	Biased	0.518	0.5053	-0.0127
11	30	Biased	0.5179	0.5105	-0.0074
12	0	Correlation	0.5167	0.5168	0.0001
13	0	Correlation	0.5188	0.5186	-0.0002
14	50	Unbiased	0.5162	0.5147	-0.0015
15	20	Biased	0.5188	0.512	-0.0068
16	20	Unbiased	0.5207	0.5209	0.0002
17	20	Biased	0.5127	0.5081	-0.0046
18	20	Unbiased	0.5168	0.5159	-0.0009
19	20	Biased	0.5153	0.5099	-0.0054
20	50	Unbiased	0.5175	0.5182	0.0007
21	0	Correlation	0.518	0.5182	0.0002
22	50	Unbiased	0.5153	0.5162	0.0009
23	0	Correlation	0.518	0.5181	0.0001
24	20	Biased	0.522	0.5166	-0.0054
26	50	Biased	0.5208	0.5094	-0.0114
27	30	Unbiased	0.5222	0.523	0.0008
28	30	Biased	0.5194	0.5107	-0.0087
29	30	Unbiased	0.5187	0.5181	-0.0006
30	20	Biased	0.518	0.5128	-0.0052
31	30	Unbiased	0.5148	0.5148	0
33	30	Biased	0.5202	0.5113	-0.0089
34	50	Unbiased	0.5174	0.5161	-0.0013
35	20	Unbiased	0.5174	0.518	0.0006
41	30	Biased	0.5194	0.5223	0.0029

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.5167	0.51788	0.5188	0.00086939	0.5168	0.51792	0.5186	0.00078049	-0.0002	5e-05	0.0002	0.00017321
20	0.5127	0.51778	0.522	0.0026195	0.5081	0.51503	0.5209	0.0041264	-0.0068	-0.00275	0.0008	0.0029744
30	0.5148	0.51852	0.5222	0.0023743	0.5099	0.51565	0.523	0.0051204	-0.0089	-0.00287	0.0029	0.0044779
50	0.5148	0.51754	0.5208	0.0018987	0.5031	0.51116	0.5182	0.00603	-0.014	-0.00638	0.0009	0.0062563

Device Test: 16.4 LEVEL|EN_RISE/EN/5/5/0/0/5/500kHz//@V_EN_RISE





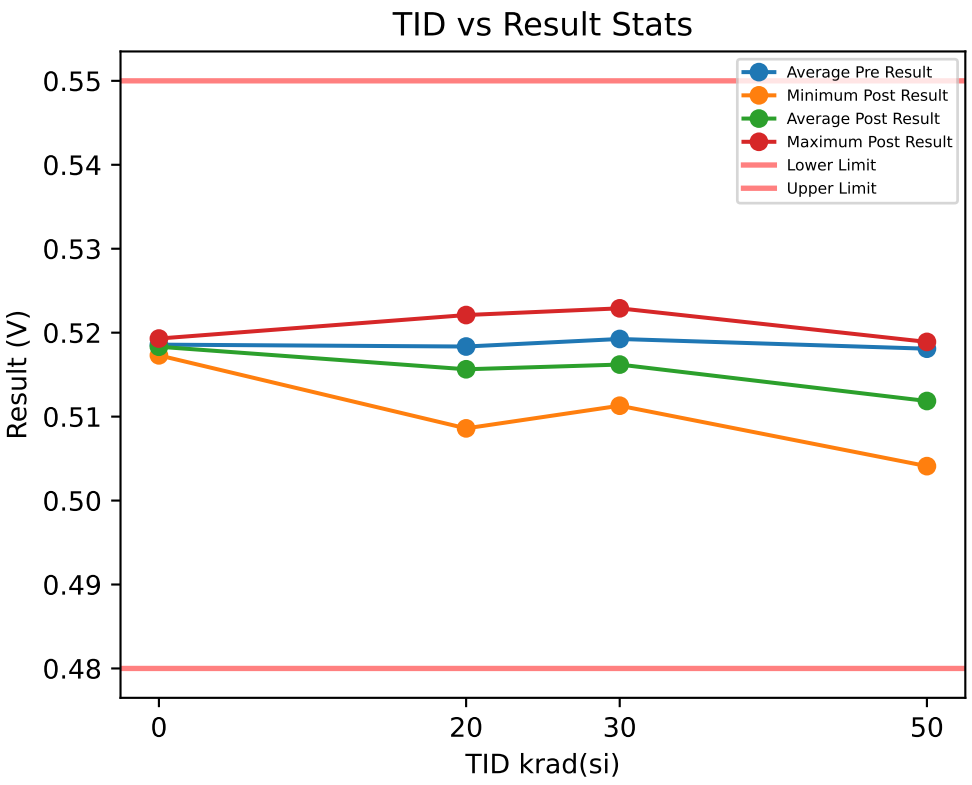
Test Results (Lower Limit = 0.57, Upper Limit = 0.66 (V))

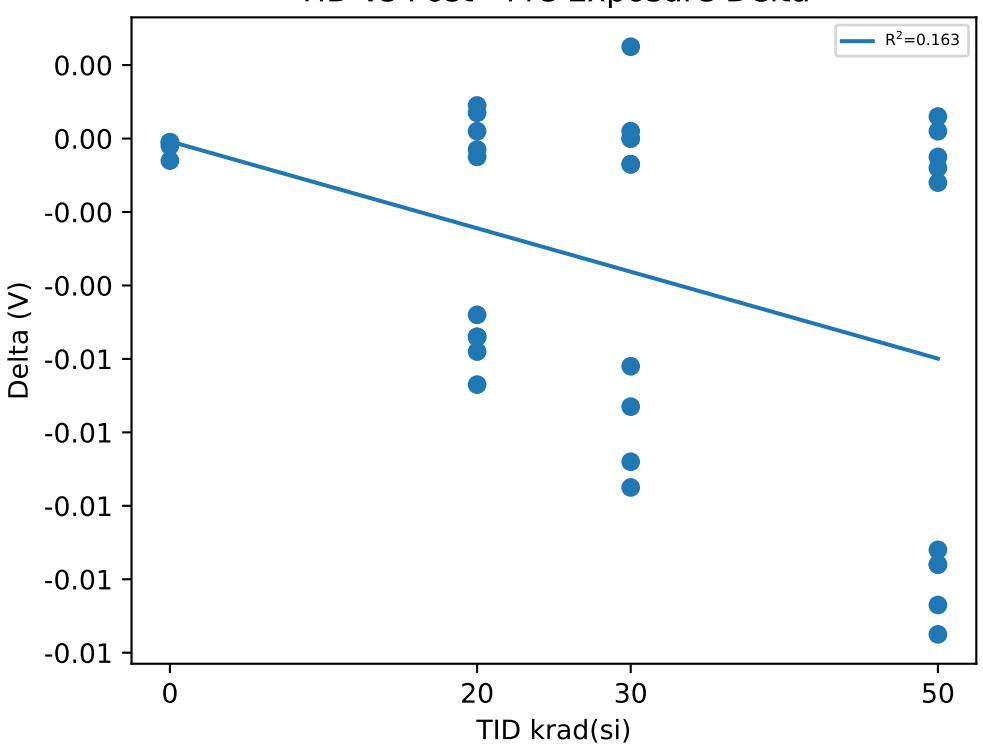
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	0.6286	0.6144	-0.0142
2	20	Unbiased	0.6268	0.6266	-0.0002
3	50	Biased	0.624	0.6124	-0.0116
4	30	Unbiased	0.6244	0.6242	-0.0002
5	50	Unbiased	0.6293	0.6281	-0.0012
6	30	Biased	0.6267	0.6208	-0.0059
7	50	Biased	0.6258	0.6145	-0.0113
8	30	Unbiased	0.6299	0.6301	0.0002
9	20	Unbiased	0.6279	0.6273	-0.0006
10	50	Biased	0.6271	0.6146	-0.0125
11	30	Biased	0.6272	0.6206	-0.0066
12	0	Correlation	0.6266	0.6266	0
13	0	Correlation	0.6279	0.6286	0.0007
14	50	Unbiased	0.6248	0.6241	-0.0007
15	20	Biased	0.6281	0.6218	-0.0063
16	20	Unbiased	0.6306	0.6312	0.0006
17	20	Biased	0.6219	0.6166	-0.0053
18	20	Unbiased	0.6253	0.6251	-0.0002
19	20	Biased	0.6245	0.6198	-0.0047
20	50	Unbiased	0.6273	0.6273	0
21	0	Correlation	0.6273	0.6272	-0.0001
22	50	Unbiased	0.6245	0.6246	0.0001
23	0	Correlation	0.6267	0.6265	-0.0002
24	20	Biased	0.6319	0.626	-0.0059
26	50	Biased	0.63	0.6184	-0.0116
27	30	Unbiased	0.6316	0.6322	0.0006
28	30	Biased	0.6286	0.619	-0.0096
29	30	Unbiased	0.628	0.628	0
30	20	Biased	0.6272	0.622	-0.0052
31	30	Unbiased	0.6243	0.6246	0.0003
33	30	Biased	0.6293	0.6205	-0.0088
34	50	Unbiased	0.6265	0.6259	-0.0006
35	20	Unbiased	0.6273	0.628	0.0007
41	30	Biased	0.6293	0.6322	0.0029

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.6266	0.62713	0.6279	0.00060208	0.6265	0.62723	0.6286	0.00096738	-0.0002	0.0001	0.0007	0.00040825
20	0.6219	0.62715	0.6319	0.0028691	0.6166	0.62444	0.6312	0.0043462	-0.0063	-0.00271	0.0007	0.0029734
30	0.6243	0.62793	0.6316	0.0023391	0.619	0.62522	0.6322	0.00508	-0.0096	-0.00271	0.0029	0.004515
50	0.624	0.62679	0.63	0.0020626	0.6124	0.62043	0.6281	0.0061547	-0.0142	-0.00636	0.0001	0.0062584

Device Test: 16.5 LEVEL|EN_FALL/EN/5/5/0/0/5/500kHz//@V_EN_FALL





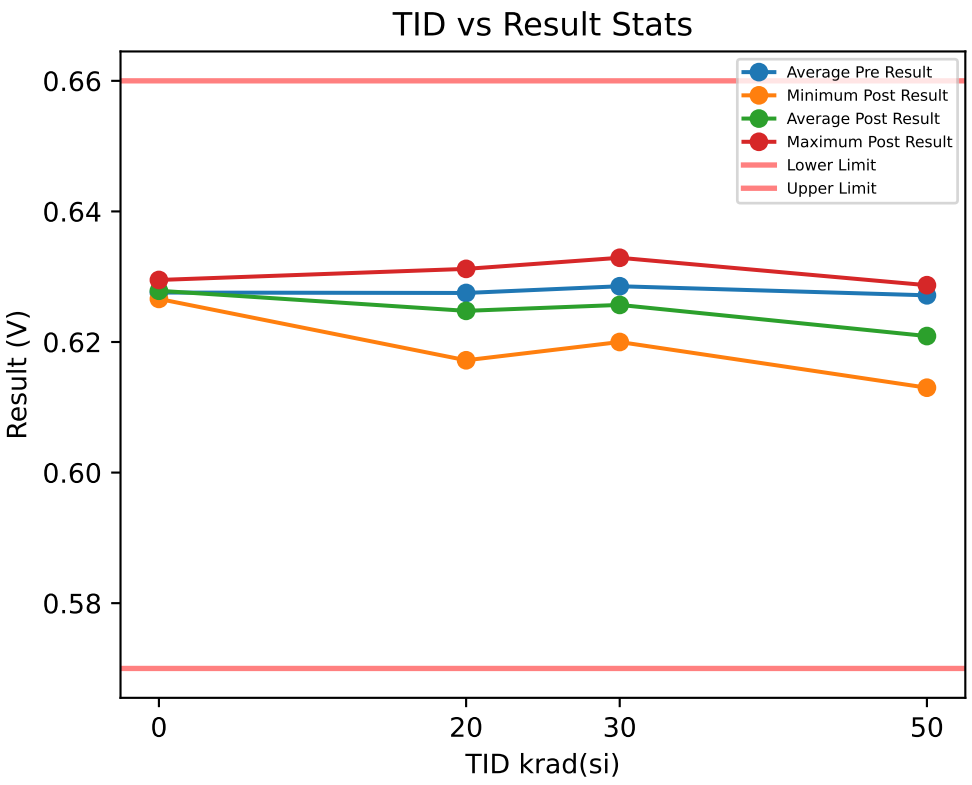
Test Results (Lower Limit = 0.48, Upper Limit = 0.55 (V))

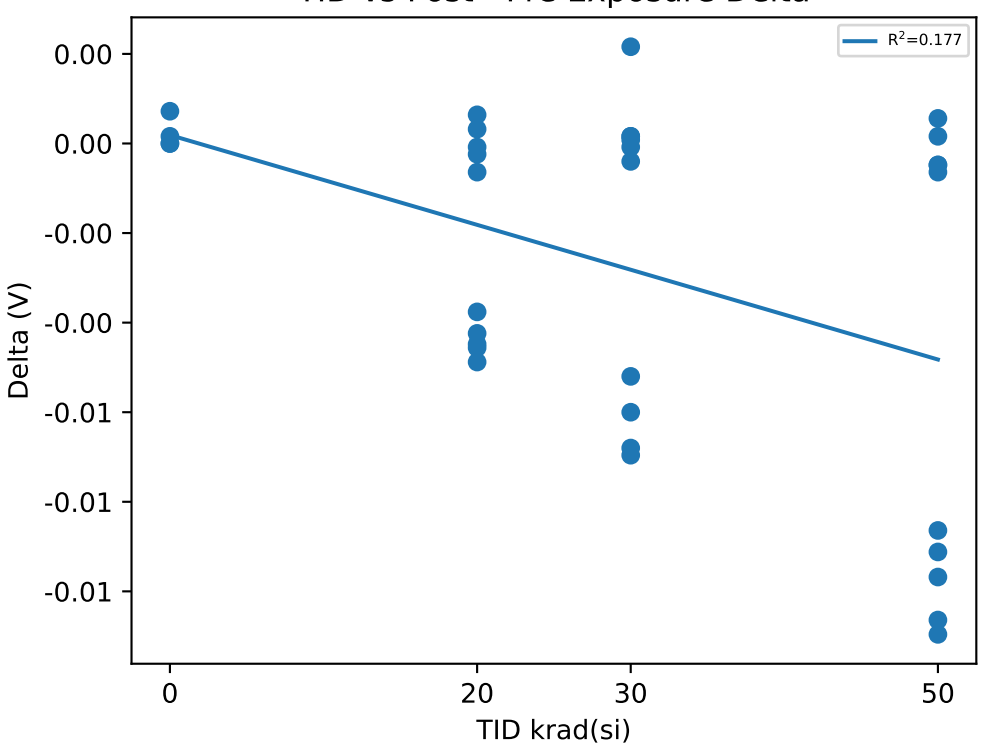
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	0.5193	0.5058	-0.0135
2	20	Unbiased	0.5182	0.5179	-0.0003
3	50	Biased	0.5153	0.5041	-0.0112
4	30	Unbiased	0.5161	0.5154	-0.0007
5	50	Unbiased	0.52	0.5188	-0.0012
6	30	Biased	0.5175	0.5113	-0.0062
7	50	Biased	0.5174	0.5058	-0.0116
8	30	Unbiased	0.5214	0.5214	0
9	20	Unbiased	0.5193	0.5188	-0.0005
10	50	Biased	0.5188	0.5061	-0.0127
11	30	Biased	0.5188	0.5115	-0.0073
12	0	Correlation	0.5174	0.5173	-0.0001
13	0	Correlation	0.5194	0.5193	-0.0001
14	50	Unbiased	0.5162	0.5157	-0.0005
15	20	Biased	0.5194	0.5127	-0.0067
16	20	Unbiased	0.5214	0.5221	0.0007
17	20	Biased	0.5134	0.5086	-0.0048
18	20	Unbiased	0.5165	0.5167	0.0002
19	20	Biased	0.516	0.5106	-0.0054
20	50	Unbiased	0.5187	0.5189	0.0002
21	0	Correlation	0.5188	0.5186	-0.0002
22	50	Unbiased	0.5162	0.5168	0.0006
23	0	Correlation	0.5187	0.5181	-0.0006
24	20	Biased	0.5226	0.5168	-0.0058
26	50	Biased	0.5215	0.5099	-0.0116
27	30	Unbiased	0.5227	0.5229	0.0002
28	30	Biased	0.5201	0.5113	-0.0088
29	30	Unbiased	0.5188	0.5188	0
30	20	Biased	0.5188	0.5134	-0.0054
31	30	Unbiased	0.516	0.5153	-0.0007
33	30	Biased	0.5208	0.5113	-0.0095
34	50	Unbiased	0.5175	0.5167	-0.0008
35	20	Unbiased	0.5179	0.5188	0.0009
41	30	Biased	0.5203	0.5228	0.0025

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.5174	0.51858	0.5194	0.00084212	0.5173	0.51832	0.5193	0.00084212	-0.0006	-0.00025	-0.0001	0.00023805
20	0.5134	0.51835	0.5226	0.0026509	0.5086	0.51564	0.5221	0.0041887	-0.0067	-0.00271	0.0009	0.0031292
30	0.516	0.51925	0.5227	0.0022287	0.5113	0.5162	0.5229	0.0049196	-0.0095	-0.00305	0.0025	0.0043927
50	0.5153	0.51809	0.5215	0.0019255	0.5041	0.51186	0.5189	0.0060643	-0.0135	-0.00623	0.0006	0.0062601

Device Test: 16.7 LEVEL|EN_RISE/EN/12/12/0/0/5/500kHz//@V_EN_RISE





Test Results (Lower Limit = 0.57, Upper Limit = 0.66 (V))

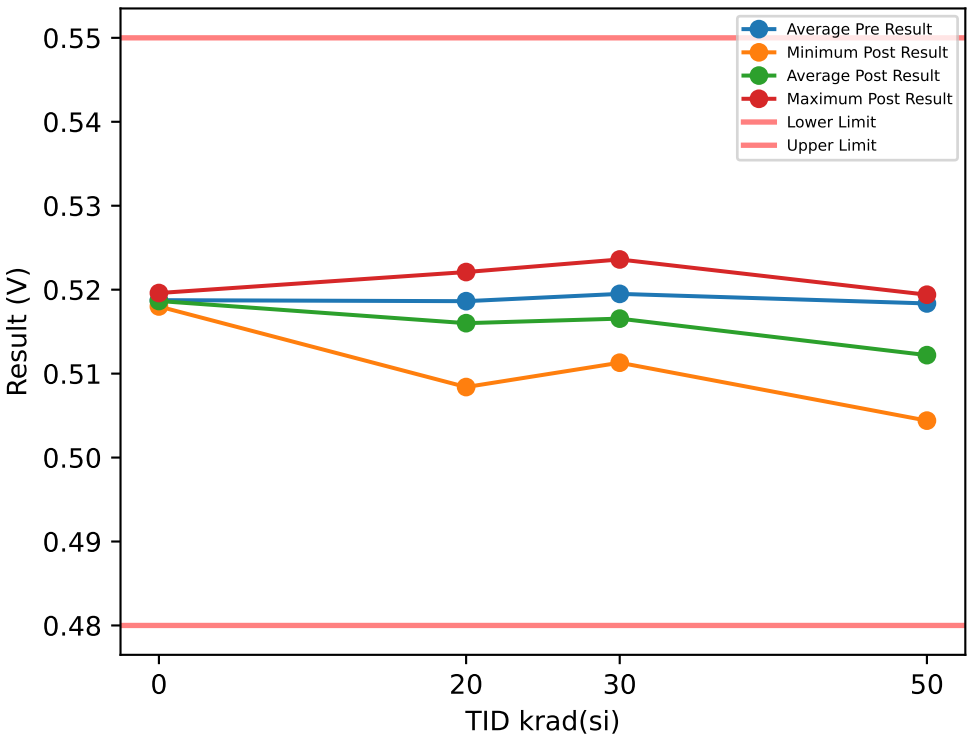
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	0.6286	0.6153	-0.0133
2	20	Unbiased	0.6266	0.6274	0.0008
3	50	Biased	0.6238	0.613	-0.0108
4	30	Unbiased	0.6251	0.6246	-0.0005
5	50	Unbiased	0.6293	0.6287	-0.0006
6	30	Biased	0.6271	0.6206	-0.0065
7	50	Biased	0.6258	0.6144	-0.0114
8	30	Unbiased	0.6306	0.6307	0.0001
9	20	Unbiased	0.6278	0.6282	0.0004
10	50	Biased	0.6282	0.6145	-0.0137
11	30	Biased	0.6281	0.6206	-0.0075
12	0	Correlation	0.6266	0.6266	0
13	0	Correlation	0.6286	0.6295	0.0009
14	50	Unbiased	0.6252	0.6246	-0.0006
15	20	Biased	0.6281	0.622	-0.0061
16	20	Unbiased	0.6315	0.6312	-0.0003
17	20	Biased	0.6225	0.6172	-0.0053
18	20	Unbiased	0.6262	0.6254	-0.0008
19	20	Biased	0.6247	0.62	-0.0047
20	50	Unbiased	0.6274	0.6281	0.0007
21	0	Correlation	0.6279	0.6279	0
22	50	Unbiased	0.6253	0.6255	0.0002
23	0	Correlation	0.6272	0.6274	0.0002
24	20	Biased	0.6321	0.6265	-0.0056
26	50	Biased	0.6306	0.6185	-0.0121
27	30	Unbiased	0.632	0.6322	0.0002
28	30	Biased	0.6285	0.62	-0.0085
29	30	Unbiased	0.6286	0.6288	0.0002
30	20	Biased	0.6275	0.6218	-0.0057
31	30	Unbiased	0.6253	0.6252	-0.0001
33	30	Biased	0.6299	0.6212	-0.0087
34	50	Unbiased	0.6273	0.6265	-0.0008
35	20	Unbiased	0.6281	0.628	-0.0001
41	30	Biased	0.6302	0.6329	0.0027

Test Statistics (V)

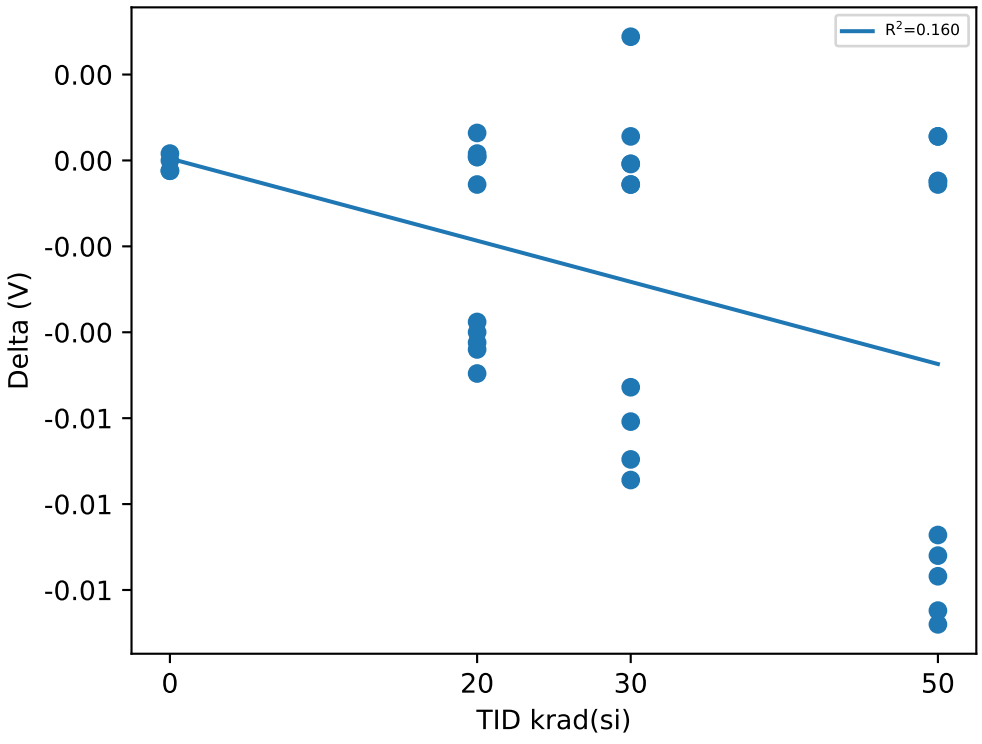
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.6266	0.62757	0.6286	0.00086554	0.6266	0.62785	0.6295	0.0012234	0	0.000275	0.0009	0.0004272
20	0.6225	0.62751	0.6321	0.002854	0.6172	0.62477	0.6312	0.0043513	-0.0061	-0.00274	0.0008	0.0029383
30	0.6251	0.62854	0.632	0.0022466	0.62	0.62568	0.6329	0.005109	-0.0087	-0.00286	0.0027	0.0043752
50	0.6238	0.62715	0.6306	0.0021104	0.613	0.62091	0.6287	0.0063388	-0.0137	-0.00624	0.0007	0.0064127

Device Test: 16.8 LEVEL|EN_FALL/EN/12/12/0/0/5/500kHz//@V_EN_FALL

TID vs Result Stats



TID vs Post - Pre Exposure Delta



Test Results (Lower Limit = 0.48, Upper Limit = 0.55 (V))

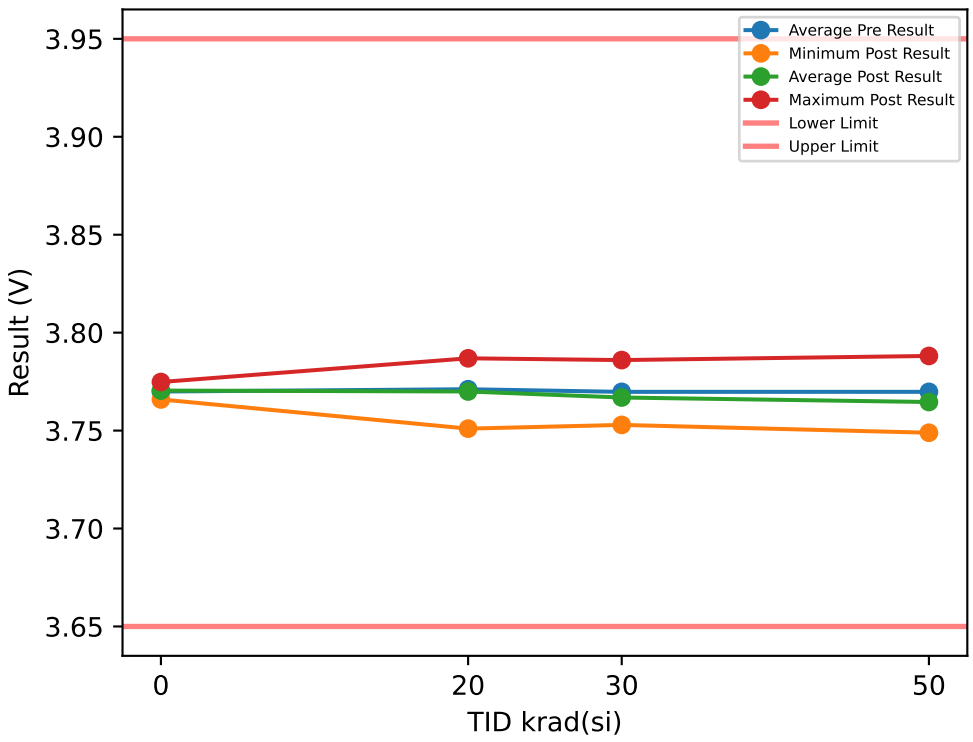
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	0.5194	0.5059	-0.0135
2	20	Unbiased	0.518	0.5188	0.0008
3	50	Biased	0.5153	0.5044	-0.0109
4	30	Unbiased	0.5161	0.5154	-0.0007
5	50	Unbiased	0.52	0.5194	-0.0006
6	30	Biased	0.5179	0.5113	-0.0066
7	50	Biased	0.5182	0.5061	-0.0121
8	30	Unbiased	0.5221	0.5214	-0.0007
9	20	Unbiased	0.5193	0.5194	0.0001
10	50	Biased	0.519	0.5059	-0.0131
11	30	Biased	0.5195	0.5119	-0.0076
12	0	Correlation	0.518	0.518	0
13	0	Correlation	0.5194	0.5196	0.0002
14	50	Unbiased	0.5168	0.5162	-0.0006
15	20	Biased	0.5194	0.5132	-0.0062
16	20	Unbiased	0.5219	0.5221	0.0002
17	20	Biased	0.5139	0.5084	-0.0055
18	20	Unbiased	0.5174	0.5167	-0.0007
19	20	Biased	0.516	0.5113	-0.0047
20	50	Unbiased	0.5187	0.5194	0.0007
21	0	Correlation	0.5189	0.5186	-0.0003
22	50	Unbiased	0.5168	0.5175	0.0007
23	0	Correlation	0.5187	0.5184	-0.0003
24	20	Biased	0.5226	0.5173	-0.0053
26	50	Biased	0.5214	0.5099	-0.0115
27	30	Unbiased	0.5228	0.5235	0.0007
28	30	Biased	0.5206	0.5113	-0.0093
29	30	Unbiased	0.5193	0.5192	-0.0001
30	20	Biased	0.519	0.514	-0.005
31	30	Unbiased	0.516	0.5159	-0.0001
33	30	Biased	0.5207	0.512	-0.0087
34	50	Unbiased	0.518	0.5173	-0.0007
35	20	Unbiased	0.5188	0.5189	0.0001
41	30	Biased	0.52	0.5236	0.0036

Test Statistics (V)

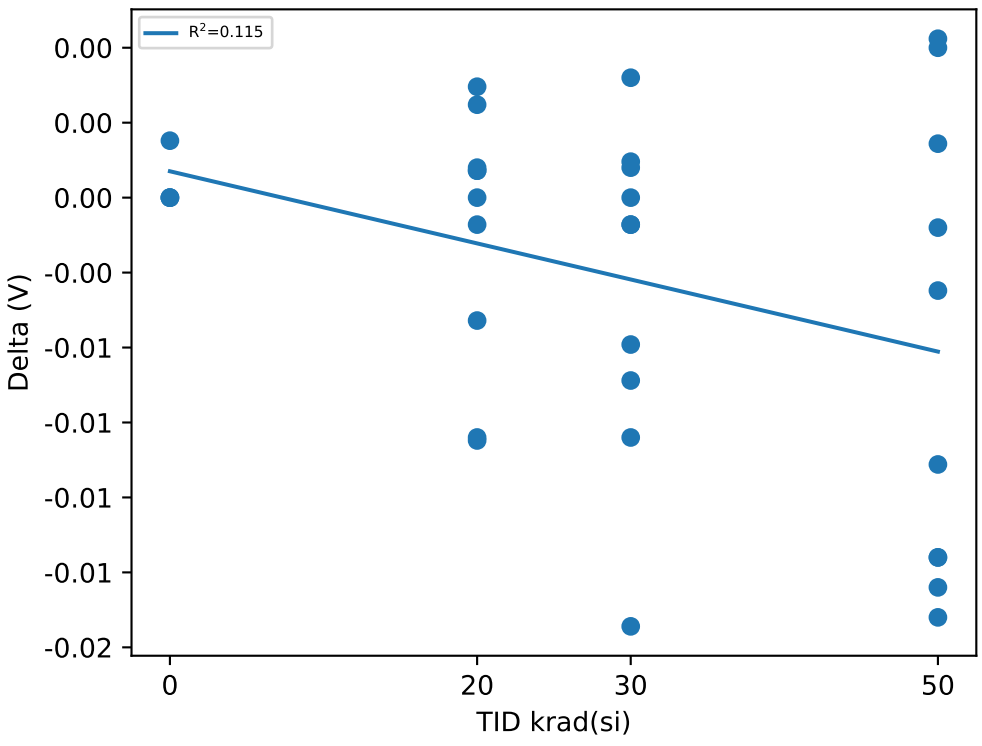
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.518	0.51875	0.5194	0.00058023	0.518	0.51865	0.5196	0.00068069	-0.0003	-0.0001	0.0002	0.00024495
20	0.5139	0.51863	0.5226	0.0025574	0.5084	0.51601	0.5221	0.0042017	-0.0062	-0.00262	0.0008	0.0029139
30	0.516	0.5195	0.5228	0.0022842	0.5113	0.51655	0.5236	0.0050304	-0.0093	-0.00295	0.0036	0.0046059
50	0.5153	0.51836	0.5214	0.0017614	0.5044	0.5122	0.5194	0.0062937	-0.0135	-0.00616	0.0007	0.0064469

Device Test: 17.1 UVLO|PVIN_RISE/PVIN/4.5/4.5/0/1000/4.5/100kHz//@PVIN_UVLO_RISE

TID vs Result Stats



TID vs Post - Pre Exposure Delta



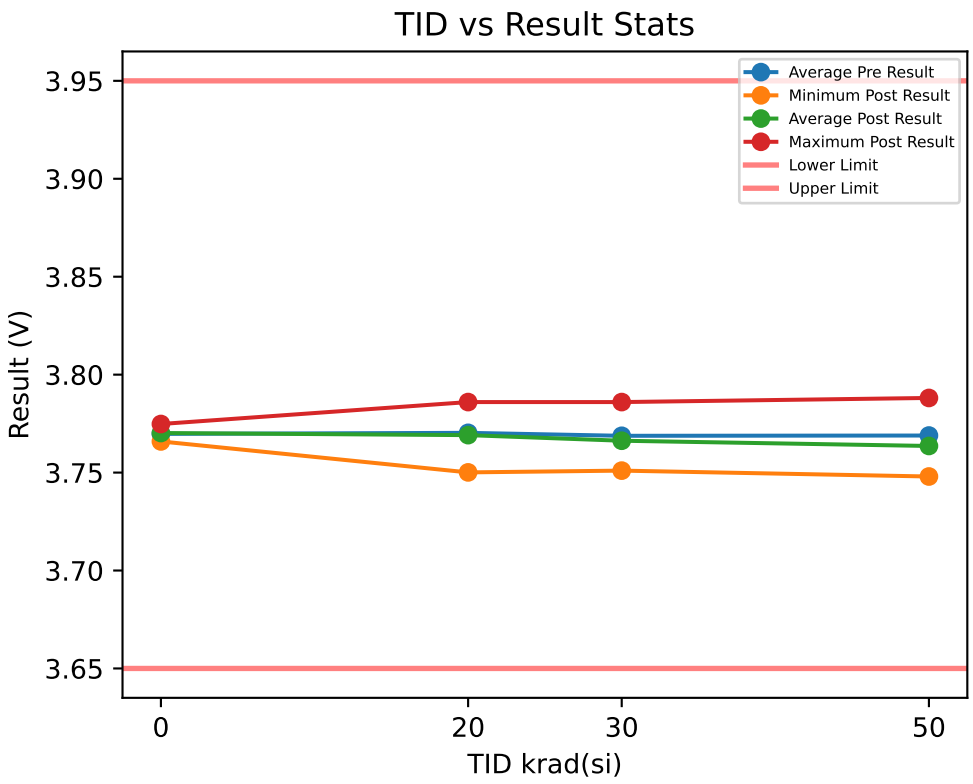
Test Results (Lower Limit = 3.65, Upper Limit = 3.95 (V))

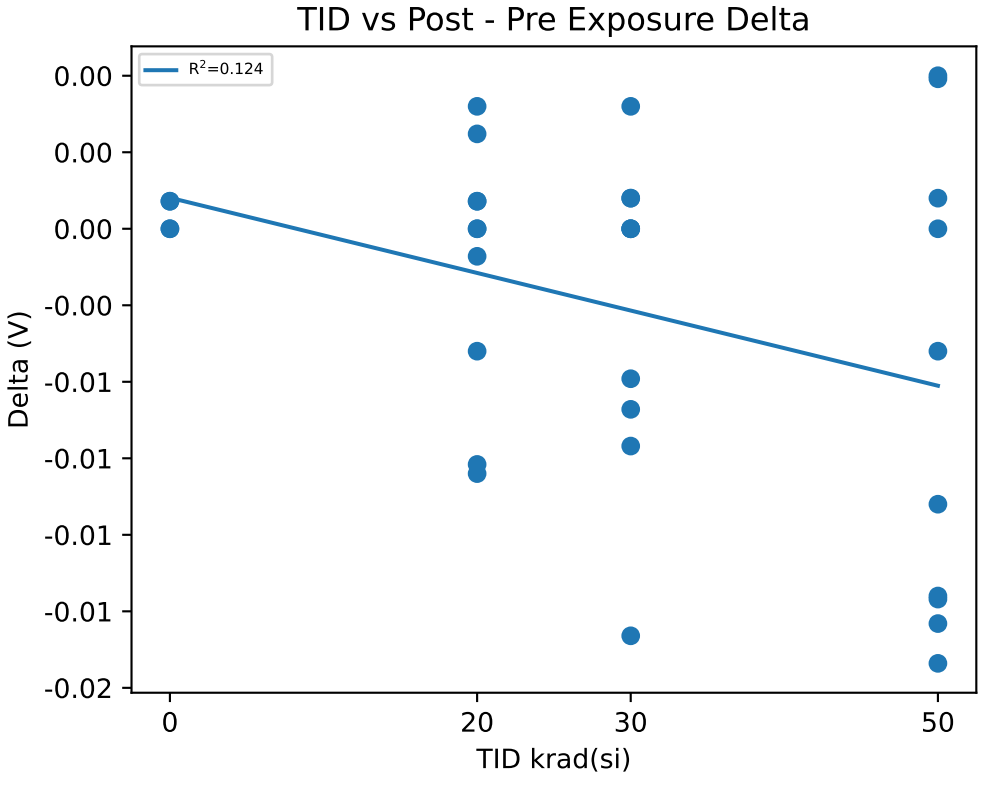
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	3.764	3.752	-0.012
2	20	Unbiased	3.7551	3.756	0.0009
3	50	Biased	3.7619	3.7489	-0.013
4	30	Unbiased	3.7869	3.786	-0.0009
5	50	Unbiased	3.7891	3.7881	-0.001
6	30	Biased	3.7711	3.765	-0.0061
7	50	Biased	3.764	3.752	-0.012
8	30	Unbiased	3.7699	3.769	-0.0009
9	20	Unbiased	3.786	3.7869	0.0009
10	50	Biased	3.7851	3.7711	-0.014
11	30	Biased	3.773	3.765	-0.008
12	0	Correlation	3.7659	3.7659	0
13	0	Correlation	3.768	3.7699	0.0019
14	50	Unbiased	3.7569	3.7619	0.005
15	20	Biased	3.781	3.782	0.001
16	20	Unbiased	3.7619	3.765	0.0031
17	20	Biased	3.764	3.756	-0.008
18	20	Unbiased	3.7699	3.769	-0.0009
19	20	Biased	3.7779	3.7779	0
20	50	Unbiased	3.7721	3.7739	0.0018
21	0	Correlation	3.7711	3.7711	0
22	50	Unbiased	3.769	3.7659	-0.0031
23	0	Correlation	3.7748	3.7748	0
24	20	Biased	3.7851	3.781	-0.0041
26	50	Biased	3.7609	3.752	-0.0089
27	30	Unbiased	3.7699	3.7699	0
28	30	Biased	3.7578	3.7529	-0.0049
29	30	Unbiased	3.7671	3.7711	0.004
30	20	Biased	3.7591	3.751	-0.0081
31	30	Unbiased	3.7619	3.7631	0.0012
33	30	Biased	3.7721	3.7578	-0.0143
34	50	Unbiased	3.7748	3.7801	0.0053
35	20	Unbiased	3.7711	3.7748	0.0037
41	30	Biased	3.768	3.769	0.001

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.7659	3.7699	3.7748	0.0038751	3.7659	3.7704	3.7748	0.0036673	0	0.000475	0.0019	0.00095
20	3.7551	3.7711	3.786	0.011049	3.751	3.77	3.7869	0.012539	-0.0081	-0.00115	0.0037	0.0042154
30	3.7578	3.7698	3.7869	0.0076491	3.7529	3.7669	3.786	0.0088238	-0.0143	-0.00289	0.004	0.005439
50	3.7569	3.7698	3.7891	0.010608	3.7489	3.7646	3.7881	0.013552	-0.014	-0.00519	0.0053	0.0076724

Device Test: 17.10 UVLO|PVIN_RISE/PVIN/4.5/4.5/0/1000/4.5/500kHz//@PVIN_UVLO_RISE





Test Results (Lower Limit = 3.65, Upper Limit = 3.95 (V))

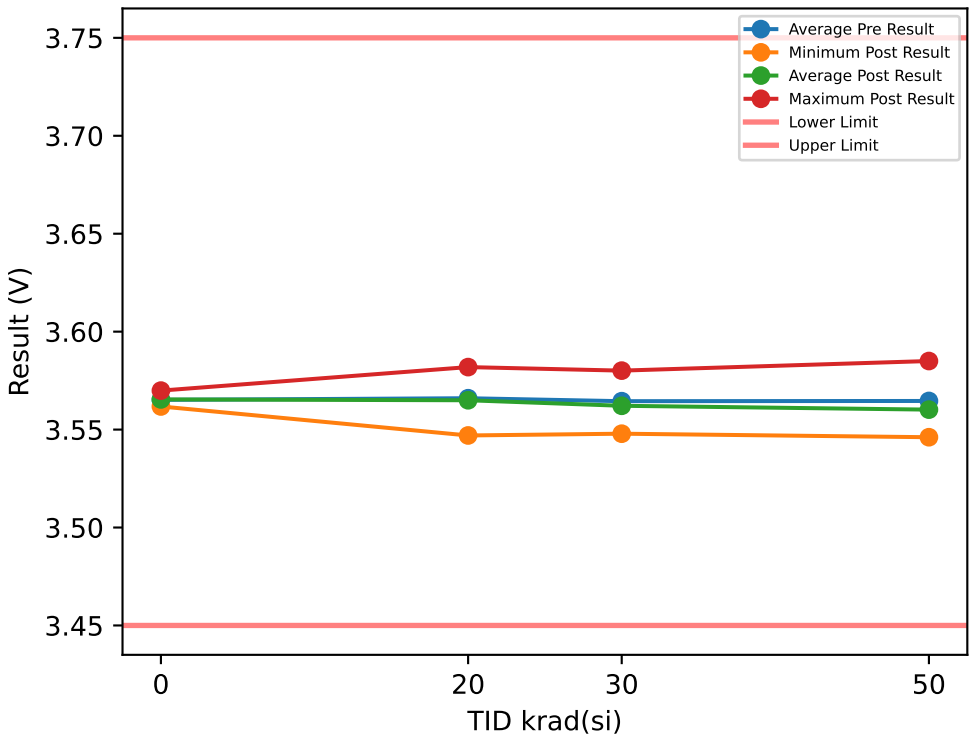
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	3.764	3.752	-0.012
2	20	Unbiased	3.7541	3.7541	0
3	50	Biased	3.7609	3.748	-0.0129
4	30	Unbiased	3.786	3.786	0
5	50	Unbiased	3.7881	3.7881	0
6	30	Biased	3.7699	3.765	-0.0049
7	50	Biased	3.7631	3.751	-0.0121
8	30	Unbiased	3.769	3.769	0
9	20	Unbiased	3.7869	3.786	-0.0009
10	50	Biased	3.7841	3.7699	-0.0142
11	30	Biased	3.7711	3.764	-0.0071
12	0	Correlation	3.765	3.7659	0.0009
13	0	Correlation	3.769	3.769	0
14	50	Unbiased	3.756	3.7609	0.0049
15	20	Biased	3.7801	3.781	0.0009
16	20	Unbiased	3.7609	3.764	0.0031
17	20	Biased	3.7631	3.7551	-0.008
18	20	Unbiased	3.769	3.769	0
19	20	Biased	3.777	3.7779	0.0009
20	50	Unbiased	3.7711	3.7721	0.001
21	0	Correlation	3.7711	3.7711	0
22	50	Unbiased	3.768	3.764	-0.004
23	0	Correlation	3.7739	3.7748	0.0009
24	20	Biased	3.7841	3.7801	-0.004
26	50	Biased	3.76	3.751	-0.009
27	30	Unbiased	3.769	3.769	0
28	30	Biased	3.7569	3.751	-0.0059
29	30	Unbiased	3.7659	3.7699	0.004
30	20	Biased	3.7578	3.7501	-0.0077
31	30	Unbiased	3.7609	3.7619	0.001
33	30	Biased	3.7711	3.7578	-0.0133
34	50	Unbiased	3.7739	3.7789	0.005
35	20	Unbiased	3.7699	3.7739	0.004
41	30	Biased	3.768	3.769	0.001

Test Statistics (V)

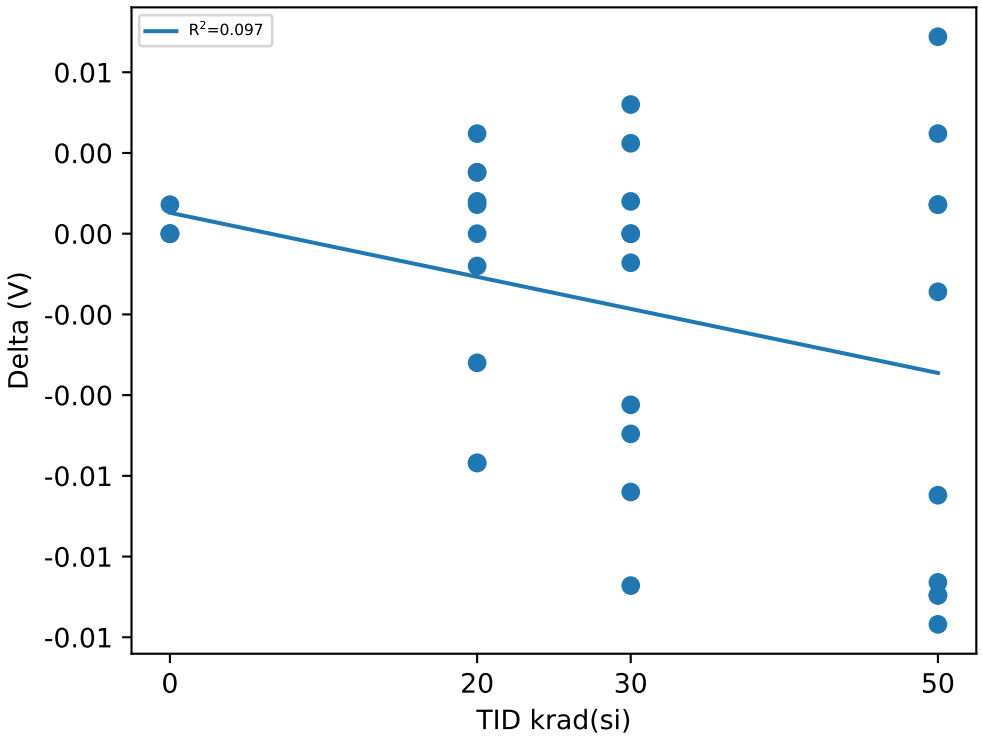
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.765	3.7698	3.7739	0.0037492	3.7659	3.7702	3.7748	0.0037372	0	0.00045	0.0009	0.00051962
20	3.7541	3.7703	3.7869	0.01139	3.7501	3.7691	3.786	0.012722	-0.008	-0.00117	0.004	0.0041317
30	3.7569	3.7688	3.786	0.0076068	3.751	3.7663	3.786	0.0091626	-0.0133	-0.00252	0.004	0.0051706
50	3.756	3.7689	3.7881	0.010528	3.748	3.7636	3.7881	0.013537	-0.0142	-0.00533	0.005	0.0076113

Device Test: 17.11 UVLO|PVIN_FALL/PVIN/4.5/4.5/0/1000/4.5/500kHz//@PVIN_UVLO_FALL

TID vs Result Stats



TID vs Post - Pre Exposure Delta



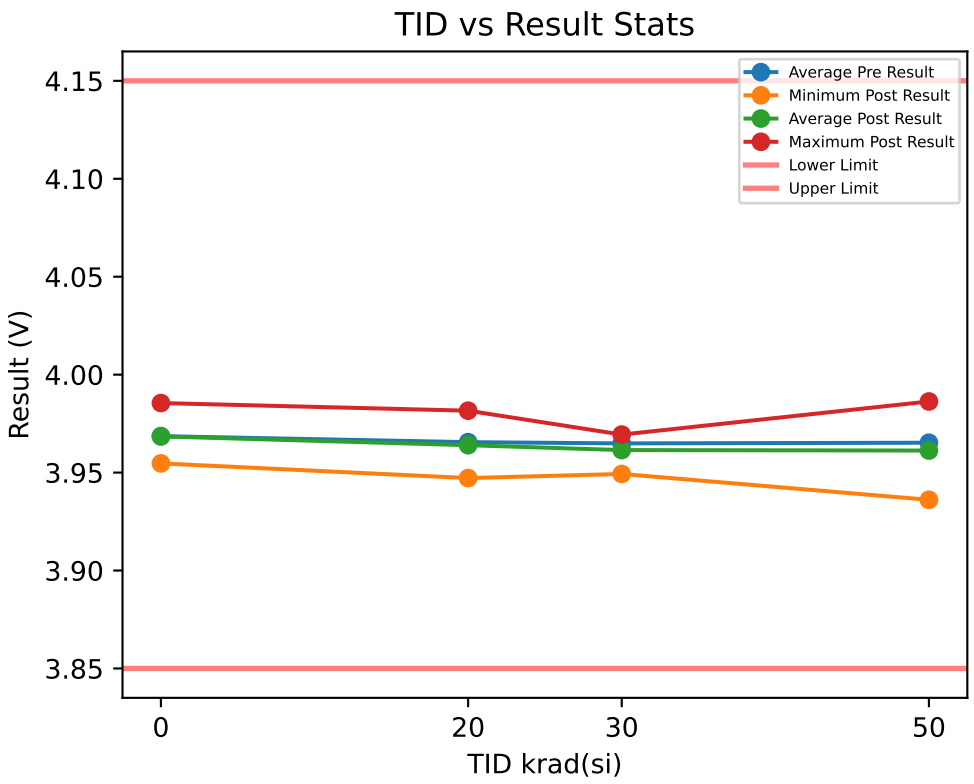
Test Results (Lower Limit = 3.45, Upper Limit = 3.75 (V))

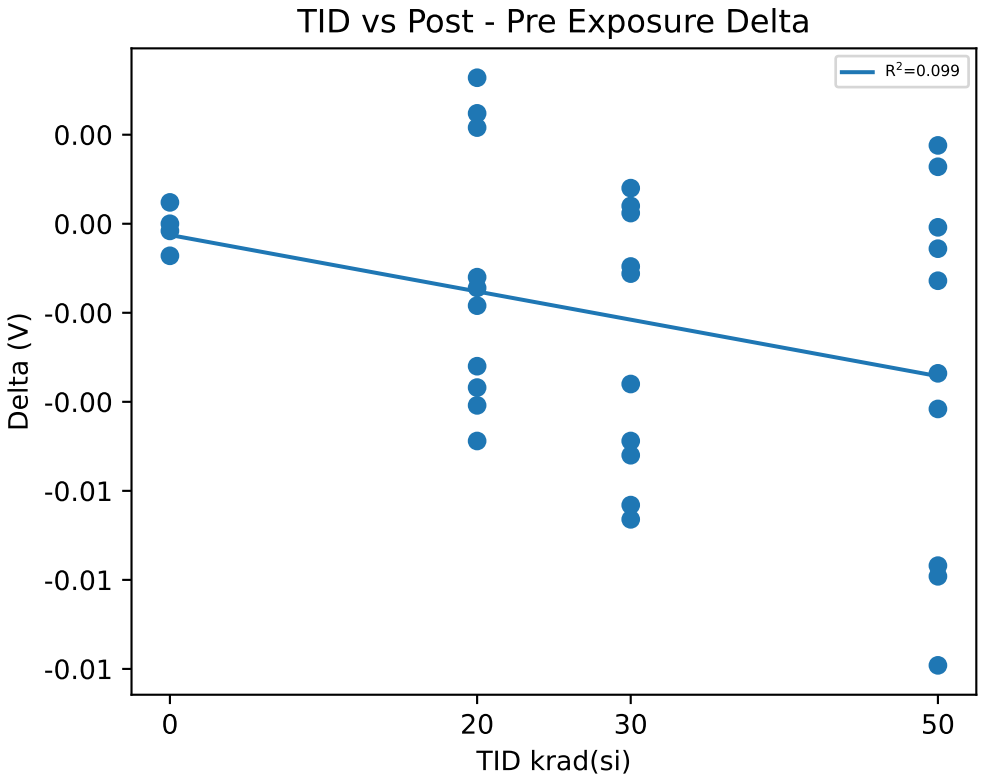
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	3.5591	3.5479	-0.0112
2	20	Unbiased	3.551	3.551	0
3	50	Biased	3.5569	3.5461	-0.0108
4	30	Unbiased	3.5801	3.5801	0
5	50	Unbiased	3.5841	3.585	0.0009
6	30	Biased	3.5671	3.5618	-0.0053
7	50	Biased	3.5591	3.5479	-0.0112
8	30	Unbiased	3.5649	3.5659	0.001
9	20	Unbiased	3.581	3.5819	0.0009
10	50	Biased	3.5801	3.568	-0.0121
11	30	Biased	3.5671	3.5591	-0.008
12	0	Correlation	3.5609	3.5618	0.0009
13	0	Correlation	3.564	3.564	0
14	50	Unbiased	3.5529	3.556	0.0031
15	20	Biased	3.5751	3.577	0.0019
16	20	Unbiased	3.5569	3.56	0.0031
17	20	Biased	3.5591	3.552	-0.0071
18	20	Unbiased	3.5659	3.5649	-0.001
19	20	Biased	3.572	3.573	0.001
20	50	Unbiased	3.5671	3.568	0.0009
21	0	Correlation	3.5659	3.5659	0
22	50	Unbiased	3.5618	3.56	-0.0018
23	0	Correlation	3.5699	3.5699	0
24	20	Biased	3.5779	3.5739	-0.004
26	50	Biased	3.556	3.5479	-0.0081
27	30	Unbiased	3.5649	3.564	-0.0009
28	30	Biased	3.5541	3.5479	-0.0062
29	30	Unbiased	3.5609	3.5649	0.004
30	20	Biased	3.5541	3.547	-0.0071
31	30	Unbiased	3.5569	3.5569	0
33	30	Biased	3.5659	3.555	-0.0109
34	50	Unbiased	3.569	3.5751	0.0061
35	20	Unbiased	3.5671	3.569	0.0019
41	30	Biased	3.5631	3.5659	0.0028

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.5609	3.5652	3.5699	0.0037642	3.5618	3.5654	3.5699	0.0034361	0	0.000225	0.0009	0.00045
20	3.551	3.566	3.581	0.010454	3.547	3.565	3.5819	0.012032	-0.0071	-0.00104	0.0031	0.0037364
30	3.5541	3.5645	3.5801	0.0069921	3.5479	3.5621	3.5801	0.0085146	-0.0109	-0.00235	0.004	0.0049415
50	3.5529	3.5646	3.5841	0.010459	3.5461	3.5602	3.585	0.013454	-0.0121	-0.00442	0.0061	0.0069591

Device Test: 17.13 UVLO|VIN_RISE/VIN/4.5/4.5/0/1000/4.5/500kHz//@VIN_UVLO_RISE





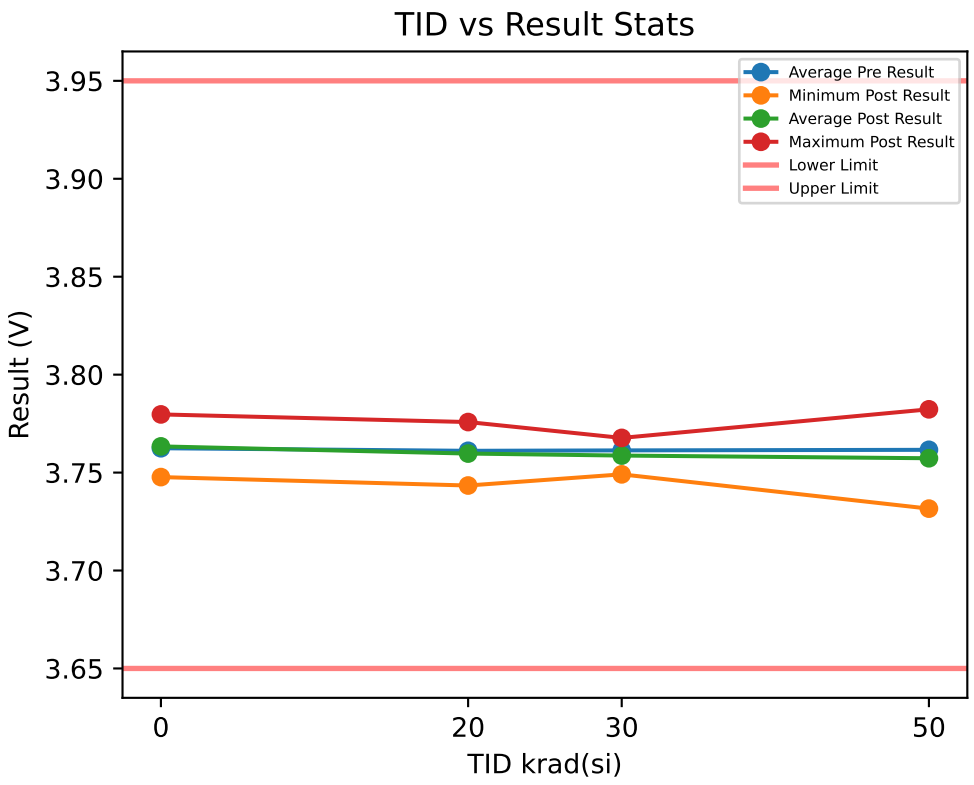
Test Results (Lower Limit = 3.85, Upper Limit = 4.15 (V))

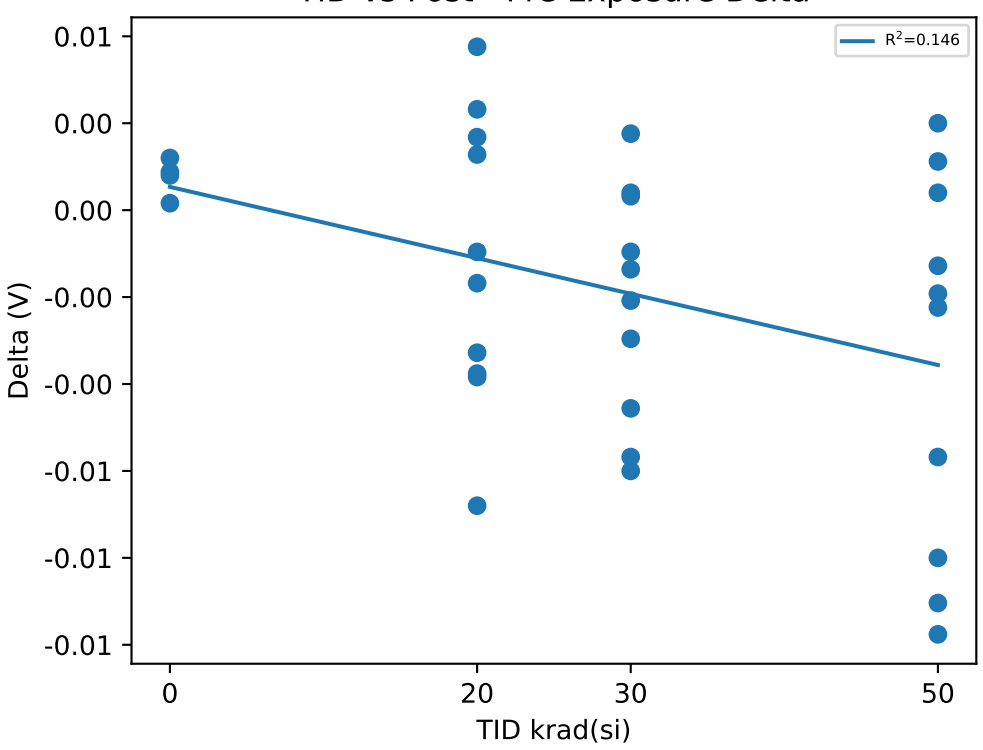
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	3.9723	3.9671	-0.0052
2	20	Unbiased	3.9627	3.9658	0.0031
3	50	Biased	3.9485	3.9361	-0.0124
4	30	Unbiased	3.9665	3.962	-0.0045
5	50	Unbiased	3.9864	3.9863	-0.0001
6	30	Biased	3.9689	3.9624	-0.0065
7	50	Biased	3.9707	3.9608	-0.0099
8	30	Unbiased	3.9706	3.9694	-0.0012
9	20	Unbiased	3.9645	3.9686	0.0041
10	50	Biased	3.9589	3.9493	-0.0096
11	30	Biased	3.9554	3.9493	-0.0061
12	0	Correlation	3.9781	3.9781	0
13	0	Correlation	3.9864	3.9855	-0.0009
14	50	Unbiased	3.9723	3.9745	0.0022
15	20	Biased	3.9701	3.9678	-0.0023
16	20	Unbiased	3.9643	3.9625	-0.0018
17	20	Biased	3.9523	3.9472	-0.0051
18	20	Unbiased	3.9664	3.9603	-0.0061
19	20	Biased	3.9651	3.9605	-0.0046
20	50	Unbiased	3.9649	3.9633	-0.0016
21	0	Correlation	3.9558	3.9556	-0.0002
22	50	Unbiased	3.9452	3.9445	-0.0007
23	0	Correlation	3.9541	3.9547	0.0006
24	20	Biased	3.9831	3.9816	-0.0015
26	50	Biased	3.9627	3.9585	-0.0042
27	30	Unbiased	3.9619	3.9536	-0.0083
28	30	Biased	3.9615	3.9618	0.0003
29	30	Unbiased	3.9595	3.9605	0.001
30	20	Biased	3.9561	3.9521	-0.004
31	30	Unbiased	3.9604	3.9609	0.0005
33	30	Biased	3.9754	3.9675	-0.0079
34	50	Unbiased	3.9705	3.9721	0.0016
35	20	Unbiased	3.9707	3.9734	0.0027
41	30	Biased	3.9689	3.9675	-0.0014

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.9541	3.9686	3.9864	0.016137	3.9547	3.9685	3.9855	0.015684	-0.0009	-0.000125	0.0006	0.00061847
20	3.9523	3.9655	3.9831	0.0083786	3.9472	3.964	3.9816	0.0099387	-0.0061	-0.00155	0.0041	0.0036643
30	3.9554	3.9649	3.9754	0.0061239	3.9493	3.9615	3.9694	0.0062198	-0.0083	-0.00341	0.001	0.0036434
50	3.9452	3.9652	3.9864	0.012172	3.9361	3.9612	3.9863	0.014992	-0.0124	-0.00399	0.0022	0.0051626

Device Test: 17.14 UVLO|VIN_FALL/VIN/4.5/4.5/0/1000/4.5/500kHz//@VIN_UVLO_FALL





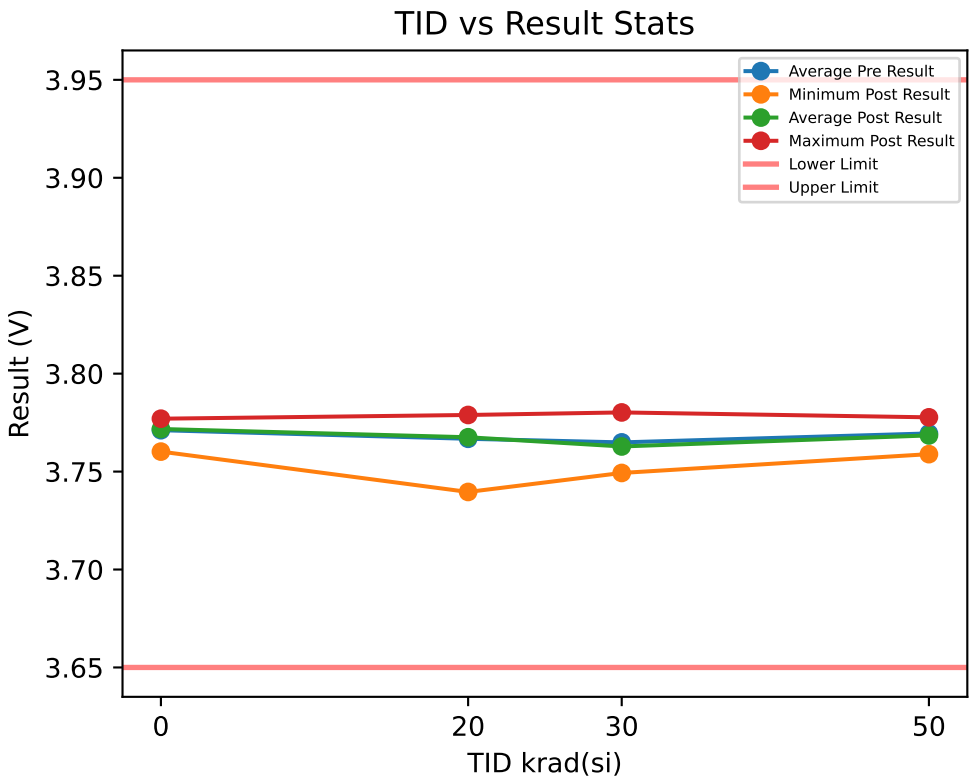
Test Results (Lower Limit = 3.65, Upper Limit = 3.95 (V))

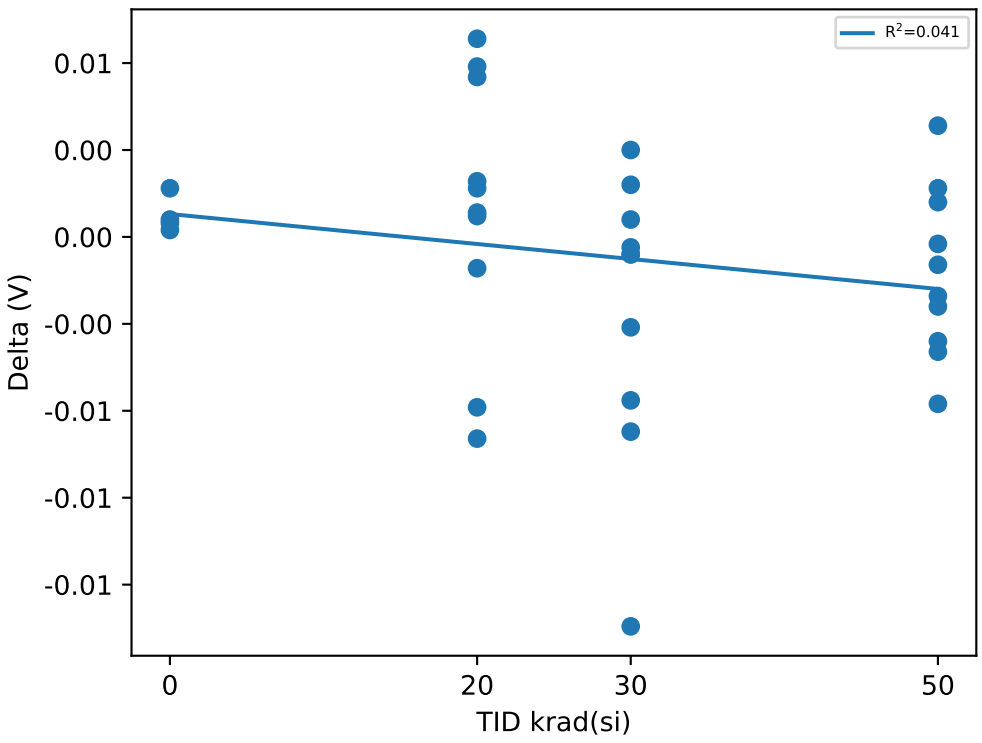
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	3.77	3.7672	-0.0028
2	20	Unbiased	3.76	3.7629	0.0029
3	50	Biased	3.7438	3.7316	-0.0122
4	30	Unbiased	3.7558	3.7563	0.0005
5	50	Unbiased	3.7809	3.7823	0.0014
6	30	Biased	3.7669	3.7594	-0.0075
7	50	Biased	3.7666	3.7566	-0.01
8	30	Unbiased	3.7689	3.7677	-0.0012
9	20	Unbiased	3.7618	3.7634	0.0016
10	50	Biased	3.7591	3.7478	-0.0113
11	30	Biased	3.7528	3.7491	-0.0037
12	0	Correlation	3.7726	3.7741	0.0015
13	0	Correlation	3.7787	3.7797	0.001
14	50	Unbiased	3.7656	3.7681	0.0025
15	20	Biased	3.7635	3.7594	-0.0041
16	20	Unbiased	3.7589	3.7577	-0.0012
17	20	Biased	3.7506	3.7458	-0.0048
18	20	Unbiased	3.7581	3.7602	0.0021
19	20	Biased	3.7641	3.7594	-0.0047
20	50	Unbiased	3.7608	3.7613	0.0005
21	0	Correlation	3.7509	3.752	0.0011
22	50	Unbiased	3.7447	3.7431	-0.0016
23	0	Correlation	3.7475	3.7477	0.0002
24	20	Biased	3.7779	3.7758	-0.0021
26	50	Biased	3.7588	3.7517	-0.0071
27	30	Unbiased	3.756	3.7534	-0.0026
28	30	Biased	3.7611	3.7594	-0.0017
29	30	Unbiased	3.7553	3.7575	0.0022
30	20	Biased	3.7519	3.7434	-0.0085
31	30	Unbiased	3.7566	3.757	0.0004
33	30	Biased	3.7731	3.766	-0.0071
34	50	Unbiased	3.7659	3.7635	-0.0024
35	20	Unbiased	3.7644	3.7691	0.0047
41	30	Biased	3.7668	3.7611	-0.0057

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.7475	3.7624	3.7787	0.015535	3.7477	3.7634	3.7797	0.015881	0.0002	0.00095	0.0015	0.00054467
20	3.7506	3.7611	3.7779	0.0075889	3.7434	3.7597	3.7758	0.0096311	-0.0085	-0.00141	0.0047	0.004185
30	3.7528	3.7613	3.7731	0.00705	3.7491	3.7587	3.7677	0.0054911	-0.0075	-0.00264	0.0022	0.0033247
50	3.7438	3.7616	3.7809	0.011154	3.7316	3.7573	3.7823	0.014447	-0.0122	-0.0043	0.0025	0.0054432

Device Test: 17.16 UVLO|VLDO_RISE/VLDO/4.5/4.5/0/1000/4.5/500kHz//@VLDO_UVLO_RISE





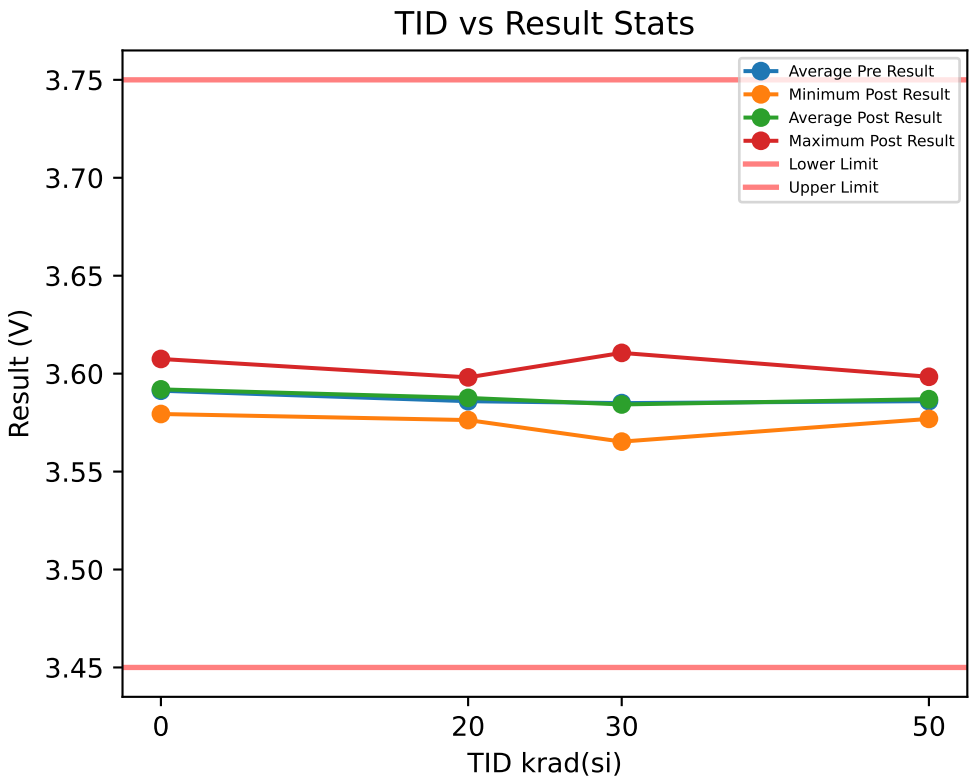
Test Results (Lower Limit = 3.65, Upper Limit = 3.95 (V))

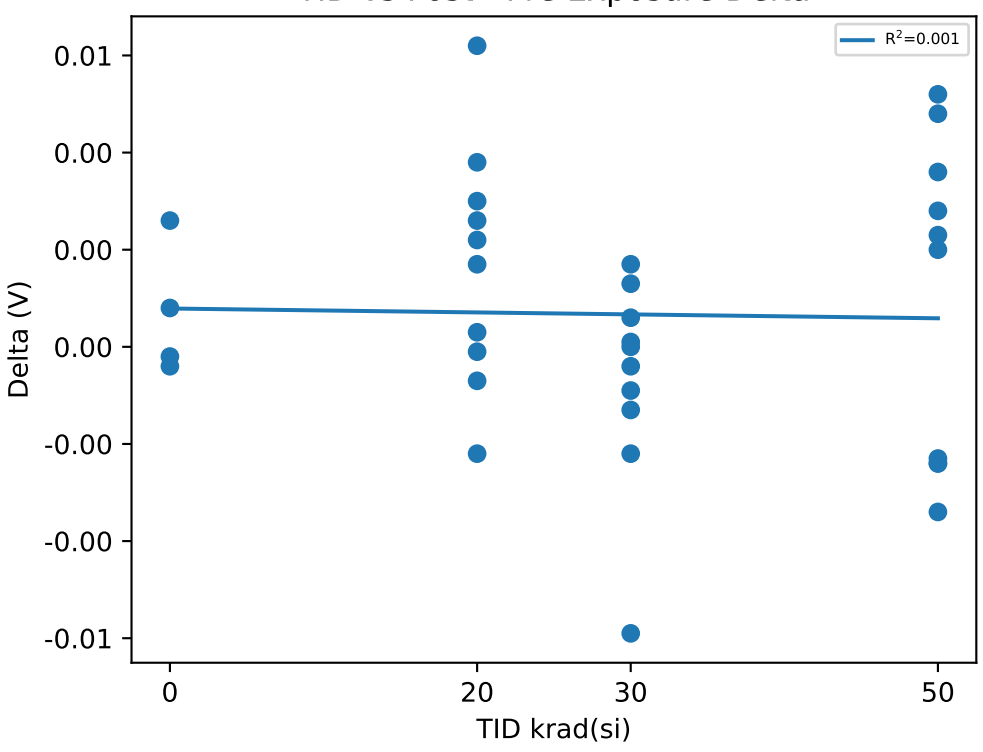
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	3.7775	3.7745	-0.003
2	20	Unbiased	3.7676	3.7692	0.0016
3	50	Biased	3.764	3.762	-0.002
4	30	Unbiased	3.7514	3.7509	-0.0005
5	50	Unbiased	3.7728	3.768	-0.0048
6	30	Biased	3.7732	3.7727	-0.0005
7	50	Biased	3.7659	3.7651	-0.0008
8	30	Unbiased	3.7683	3.7708	0.0025
9	20	Unbiased	3.7728	3.7774	0.0046
10	50	Biased	3.771	3.7693	-0.0017
11	30	Biased	3.754	3.7493	-0.0047
12	0	Correlation	3.7751	3.7765	0.0014
13	0	Correlation	3.7766	3.777	0.0004
14	50	Unbiased	3.7779	3.7777	-0.0002
15	20	Biased	3.7612	3.7618	0.0006
16	20	Unbiased	3.7798	3.7789	-0.0009
17	20	Biased	3.7454	3.7396	-0.0058
18	20	Unbiased	3.7648	3.7705	0.0057
19	20	Biased	3.7712	3.7726	0.0014
20	50	Unbiased	3.7704	3.7718	0.0014
21	0	Correlation	3.7728	3.7733	0.0005
22	50	Unbiased	3.7648	3.7615	-0.0033
23	0	Correlation	3.76	3.7602	0.0002
24	20	Biased	3.7767	3.7774	0.0007
26	50	Biased	3.7726	3.7758	0.0032
27	30	Unbiased	3.769	3.7687	-0.0003
28	30	Biased	3.7486	3.7501	0.0015
29	30	Unbiased	3.7816	3.7704	-0.0112
30	20	Biased	3.7573	3.7524	-0.0049
31	30	Unbiased	3.7575	3.758	0.0005
33	30	Biased	3.7828	3.7802	-0.0026
34	50	Unbiased	3.7579	3.7589	0.001
35	20	Unbiased	3.7706	3.7755	0.0049
41	30	Biased	3.7627	3.7571	-0.0056

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.76	3.7711	3.7766	0.0075795	3.7602	3.7717	3.777	0.0078725	0.0002	0.000625	0.0014	0.00053151
20	3.7454	3.7667	3.7798	0.010116	3.7396	3.7675	3.7789	0.012766	-0.0058	0.00079	0.0057	0.0038766
30	3.7486	3.7649	3.7828	0.012124	3.7493	3.7628	3.7802	0.011045	-0.0112	-0.00209	0.0025	0.0041003
50	3.7579	3.7695	3.7779	0.0063068	3.7589	3.7685	3.7777	0.0065035	-0.0048	-0.00102	0.0032	0.0024335

Device Test: 17.17 UVLO|VLDO_FALL/VLDO/4.5/4.5/0/1000/4.5/500kHz//@VLDO_UVLO_FALL





Test Results (Lower Limit = 3.45, Upper Limit = 3.75 (V))

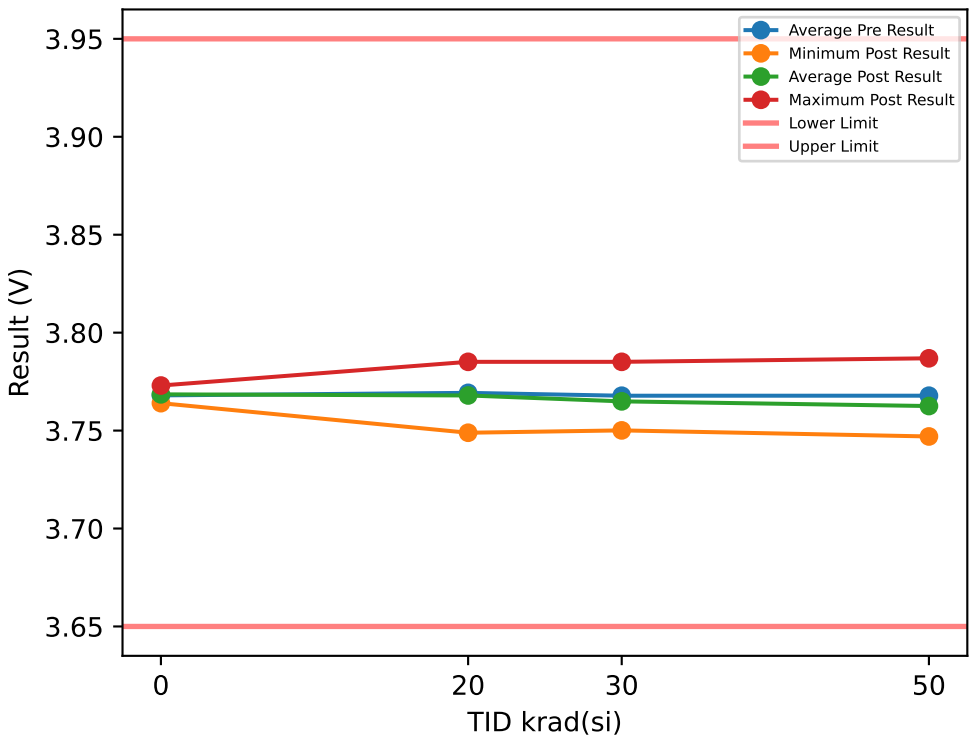
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	3.5936	3.5984	0.0048
2	20	Unbiased	3.5797	3.5775	-0.0022
3	50	Biased	3.5792	3.5769	-0.0023
4	30	Unbiased	3.5825	3.5816	-0.0009
5	50	Unbiased	3.5877	3.5897	0.002
6	30	Biased	3.5897	3.5875	-0.0022
7	50	Biased	3.5848	3.59	0.0052
8	30	Unbiased	3.5853	3.5853	0
9	20	Unbiased	3.5842	3.5904	0.0062
10	50	Biased	3.5931	3.5907	-0.0024
11	30	Biased	3.5776	3.5782	0.0006
12	0	Correlation	3.5871	3.5897	0.0026
13	0	Correlation	3.6077	3.6075	-0.0002
14	50	Unbiased	3.589	3.5913	0.0023
15	20	Biased	3.5851	3.585	-0.0001
16	20	Unbiased	3.5921	3.5947	0.0026
17	20	Biased	3.5733	3.5763	0.003
18	20	Unbiased	3.5856	3.5859	0.0003
19	20	Biased	3.5936	3.5953	0.0017
20	50	Unbiased	3.5818	3.5854	0.0036
21	0	Correlation	3.5905	3.5913	0.0008
22	50	Unbiased	3.5881	3.5857	-0.0024
23	0	Correlation	3.5798	3.5794	-0.0004
24	20	Biased	3.5943	3.5981	0.0038
26	50	Biased	3.5853	3.5819	-0.0034
27	30	Unbiased	3.5876	3.5863	-0.0013
28	30	Biased	3.5712	3.5653	-0.0059
29	30	Unbiased	3.588	3.5897	0.0017
30	20	Biased	3.5794	3.5816	0.0022
31	30	Unbiased	3.5839	3.5835	-0.0004
33	30	Biased	3.6105	3.6106	0.0001
34	50	Unbiased	3.5769	3.5797	0.0028
35	20	Unbiased	3.592	3.5913	-0.0007
41	30	Biased	3.5733	3.5746	0.0013

Test Statistics (V)

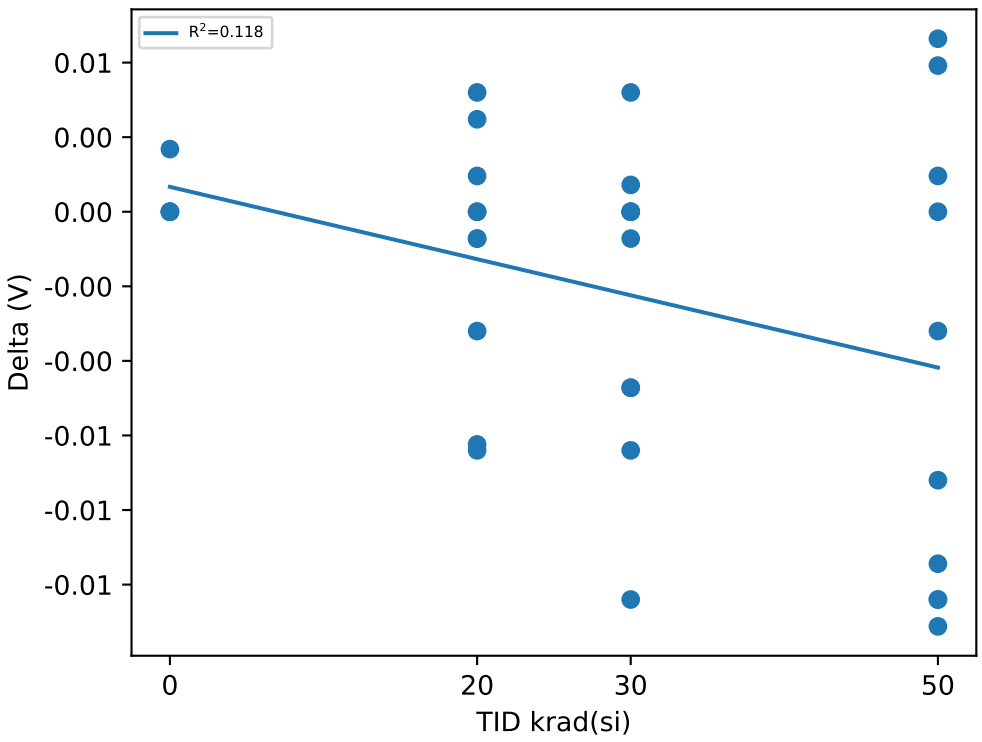
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.5798	3.5913	3.6077	0.011825	3.5794	3.592	3.6075	0.011616	-0.0004	0.0007	0.0026	0.0013711
20	3.5733	3.5859	3.5943	0.0070598	3.5763	3.5876	3.5981	0.007578	-0.0022	0.00168	0.0062	0.0024399
30	3.5712	3.585	3.6105	0.010943	3.5653	3.5843	3.6106	0.01172	-0.0059	-0.0007	0.0017	0.0021695
50	3.5769	3.5859	3.5936	0.0055082	3.5769	3.587	3.5984	0.0063594	-0.0034	0.00102	0.0052	0.0033021

Device Test: 17.19 UVLO|PVIN_RISE/PVIN/4.5/4.5/0/1000/4.5/1MHz//@PVIN_UVLO_RISE

TID vs Result Stats



TID vs Post - Pre Exposure Delta



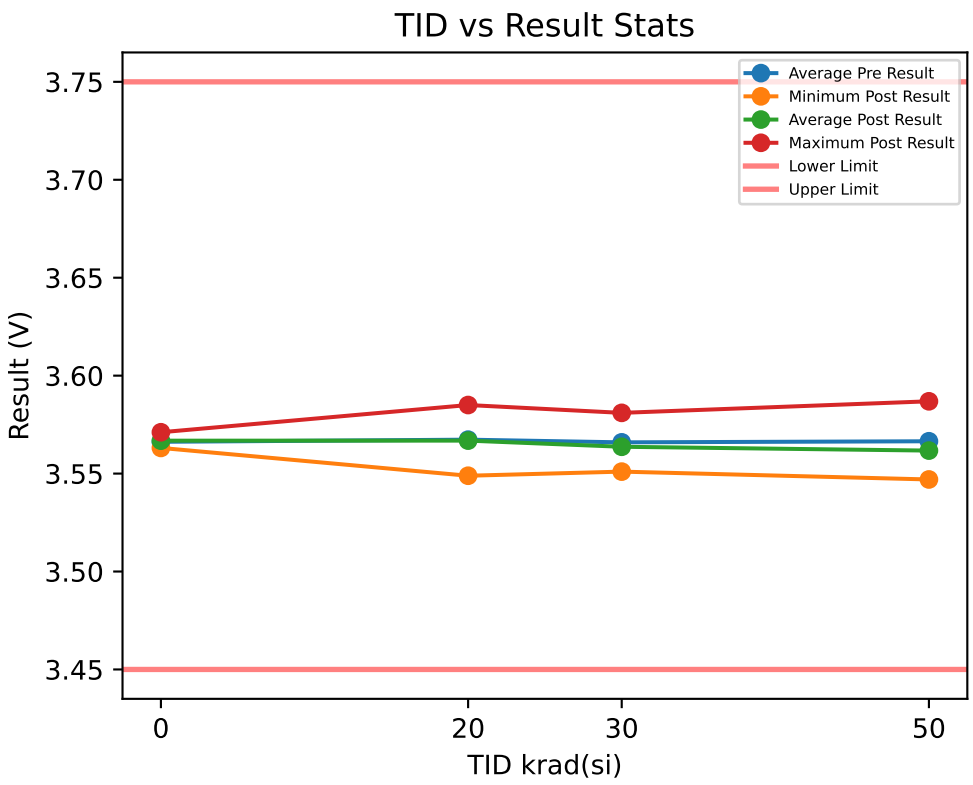
Test Results (Lower Limit = 3.65, Upper Limit = 3.95 (V))

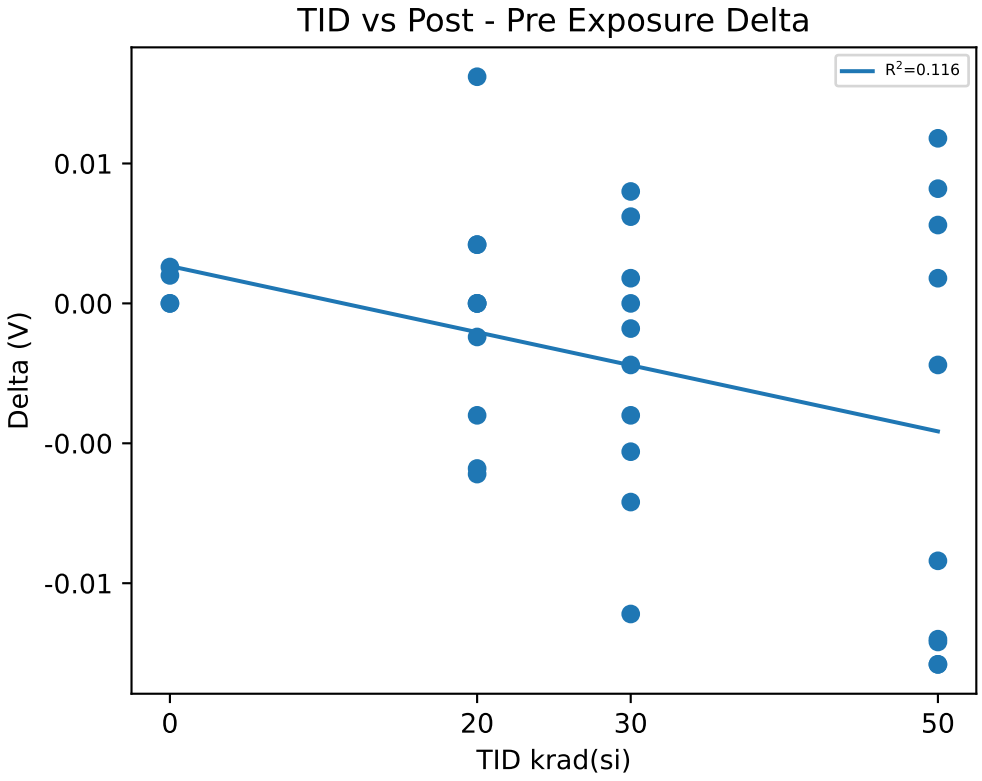
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	3.7631	3.7501	-0.013
2	20	Unbiased	3.7529	3.7529	0
3	50	Biased	3.76	3.747	-0.013
4	30	Unbiased	3.7851	3.7851	0
5	50	Unbiased	3.7869	3.7869	0
6	30	Biased	3.769	3.7631	-0.0059
7	50	Biased	3.7619	3.7501	-0.0118
8	30	Unbiased	3.768	3.7671	-0.0009
9	20	Unbiased	3.786	3.7851	-0.0009
10	50	Biased	3.7829	3.769	-0.0139
11	30	Biased	3.7699	3.7619	-0.008
12	0	Correlation	3.764	3.764	0
13	0	Correlation	3.7659	3.768	0.0021
14	50	Unbiased	3.7551	3.76	0.0049
15	20	Biased	3.7789	3.7801	0.0012
16	20	Unbiased	3.76	3.7631	0.0031
17	20	Biased	3.7619	3.7541	-0.0078
18	20	Unbiased	3.768	3.7671	-0.0009
19	20	Biased	3.7761	3.7761	0
20	50	Unbiased	3.7699	3.7711	0.0012
21	0	Correlation	3.769	3.769	0
22	50	Unbiased	3.7671	3.7631	-0.004
23	0	Correlation	3.773	3.773	0
24	20	Biased	3.7829	3.7789	-0.004
26	50	Biased	3.7591	3.7501	-0.009
27	30	Unbiased	3.768	3.768	0
28	30	Biased	3.756	3.7501	-0.0059
29	30	Unbiased	3.765	3.769	0.004
30	20	Biased	3.7569	3.7489	-0.008
31	30	Unbiased	3.76	3.7609	0.0009
33	30	Biased	3.7699	3.7569	-0.013
34	50	Unbiased	3.7721	3.7779	0.0058
35	20	Unbiased	3.769	3.773	0.004
41	30	Biased	3.7671	3.7671	0

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.764	3.768	3.773	0.0039331	3.764	3.7685	3.773	0.0036968	0	0.000525	0.0021	0.00105
20	3.7529	3.7693	3.786	0.011392	3.7489	3.7679	3.7851	0.012732	-0.008	-0.00133	0.004	0.0041072
30	3.756	3.7678	3.7851	0.0075868	3.7501	3.7649	3.7851	0.0091616	-0.013	-0.00288	0.004	0.0051348
50	3.7551	3.7678	3.7869	0.010387	3.747	3.7625	3.7869	0.013568	-0.0139	-0.00528	0.0058	0.0078014

Device Test: 17.2 UVLO|PVIN_FALL/PVIN/4.5/4.5/0/1000/4.5/100kHz//@PVIN_UVLO_FALL





Test Results (Lower Limit = 3.45, Upper Limit = 3.75 (V))

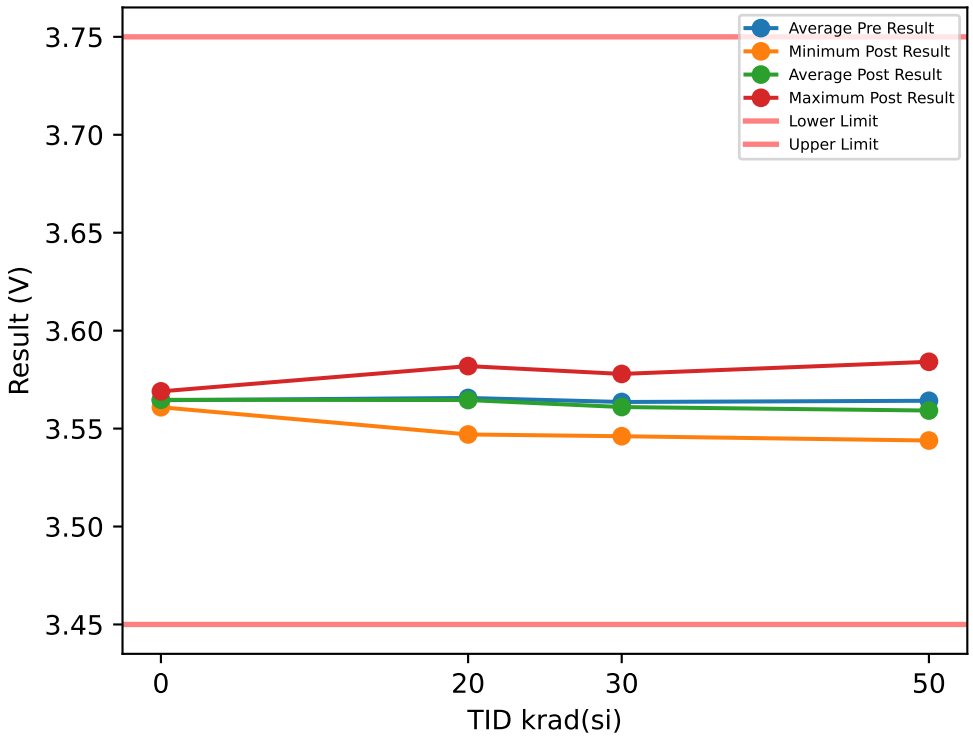
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	3.5609	3.5489	-0.012
2	20	Unbiased	3.552	3.552	0
3	50	Biased	3.5591	3.547	-0.0121
4	30	Unbiased	3.5819	3.581	-0.0009
5	50	Unbiased	3.586	3.5869	0.0009
6	30	Biased	3.5671	3.5618	-0.0053
7	50	Biased	3.5618	3.5489	-0.0129
8	30	Unbiased	3.5671	3.568	0.0009
9	20	Unbiased	3.5829	3.585	0.0021
10	50	Biased	3.5819	3.569	-0.0129
11	30	Biased	3.568	3.5609	-0.0071
12	0	Correlation	3.5618	3.5631	0.0013
13	0	Correlation	3.5649	3.5659	0.001
14	50	Unbiased	3.555	3.5591	0.0041
15	20	Biased	3.577	3.577	0
16	20	Unbiased	3.555	3.5631	0.0081
17	20	Biased	3.56	3.5541	-0.0059
18	20	Unbiased	3.5671	3.5659	-0.0012
19	20	Biased	3.5751	3.5751	0
20	50	Unbiased	3.5671	3.5699	0.0028
21	0	Correlation	3.5671	3.5671	0
22	50	Unbiased	3.564	3.5618	-0.0022
23	0	Correlation	3.5711	3.5711	0
24	20	Biased	3.5801	3.5761	-0.004
26	50	Biased	3.5581	3.5489	-0.0092
27	30	Unbiased	3.5671	3.5649	-0.0022
28	30	Biased	3.555	3.551	-0.004
29	30	Unbiased	3.5631	3.5671	0.004
30	20	Biased	3.555	3.5489	-0.0061
31	30	Unbiased	3.5591	3.5591	0
33	30	Biased	3.5671	3.556	-0.0111
34	50	Unbiased	3.5711	3.577	0.0059
35	20	Unbiased	3.569	3.5711	0.0021
41	30	Biased	3.564	3.5671	0.0031

Test Statistics (V)

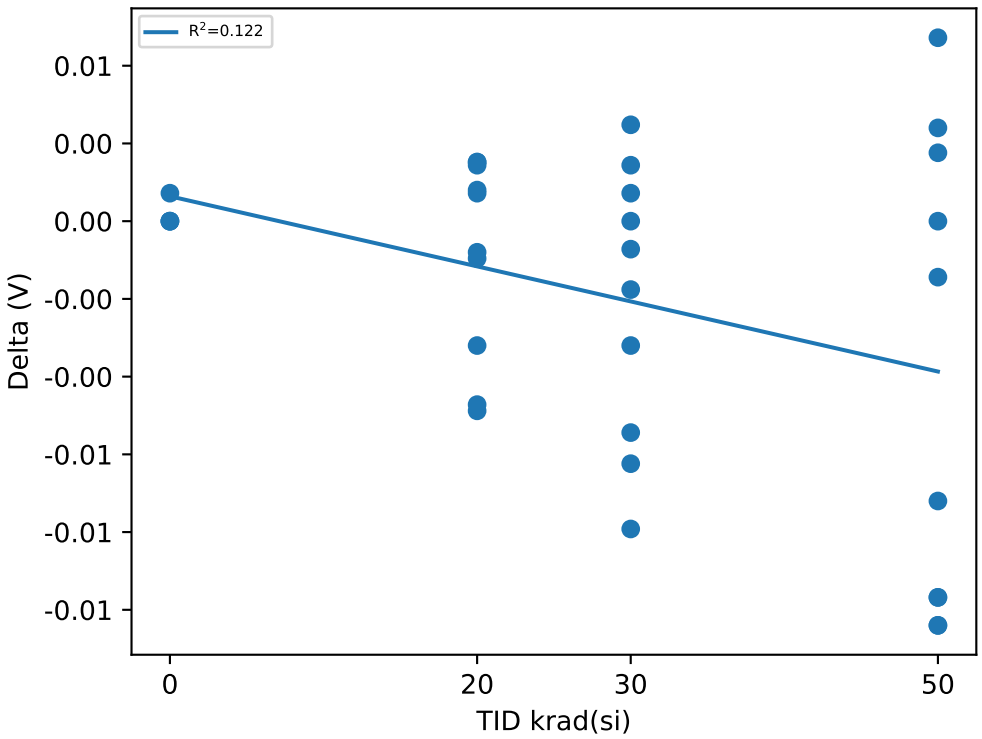
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.5618	3.5662	3.5711	0.0039101	3.5631	3.5668	3.5711	0.0033206	0	0.000575	0.0013	0.00067515
20	3.552	3.5673	3.5829	0.011329	3.5489	3.5668	3.585	0.012131	-0.0061	-0.00049	0.0081	0.0042359
30	3.555	3.5659	3.5819	0.007013	3.551	3.5637	3.581	0.0081345	-0.0111	-0.00226	0.004	0.0046987
50	3.555	3.5665	3.586	0.010307	3.547	3.5617	3.5869	0.01376	-0.0129	-0.00476	0.0059	0.0077918

Device Test: 17.20 UVLO|PVIN_FALL/PVIN/4.5/4.5/0/1000/4.5/1MHz//@PVIN_UVLO_FALL

TID vs Result Stats



TID vs Post - Pre Exposure Delta



Test Results (Lower Limit = 3.45, Upper Limit = 3.75 (V))

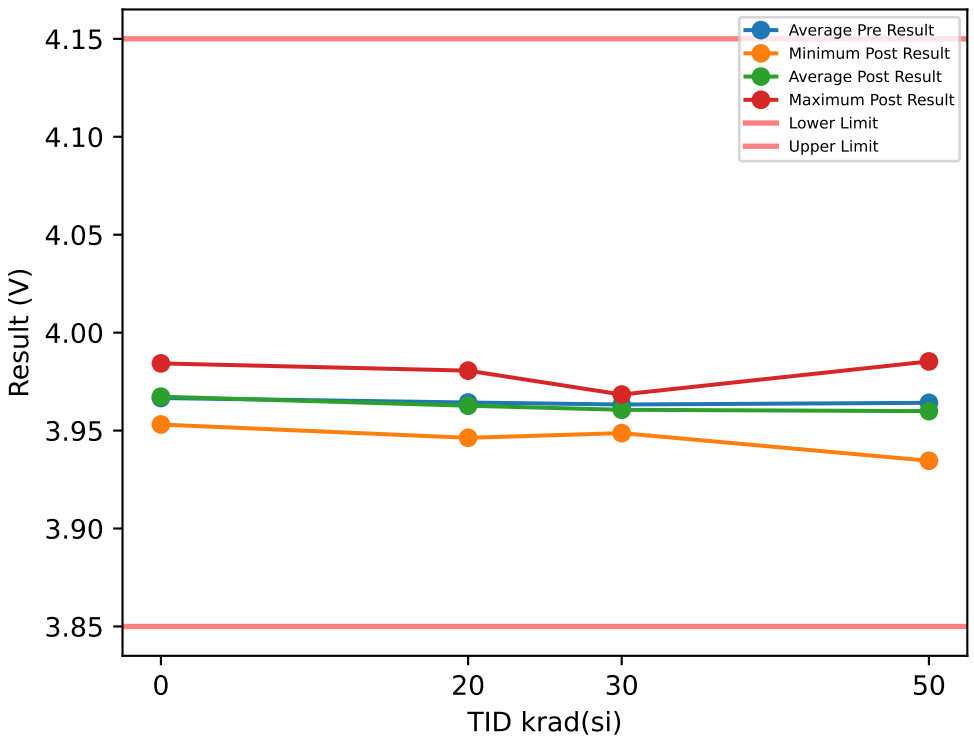
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	3.5591	3.547	-0.0121
2	20	Unbiased	3.5501	3.5489	-0.0012
3	50	Biased	3.5569	3.5439	-0.013
4	30	Unbiased	3.5801	3.5779	-0.0022
5	50	Unbiased	3.5819	3.5841	0.0022
6	30	Biased	3.564	3.56	-0.004
7	50	Biased	3.5591	3.547	-0.0121
8	30	Unbiased	3.5649	3.564	-0.0009
9	20	Unbiased	3.5801	3.5819	0.0018
10	50	Biased	3.581	3.568	-0.013
11	30	Biased	3.5659	3.5581	-0.0078
12	0	Correlation	3.5609	3.5609	0
13	0	Correlation	3.5631	3.564	0.0009
14	50	Unbiased	3.552	3.555	0.003
15	20	Biased	3.5751	3.5761	0.001
16	20	Unbiased	3.5581	3.56	0.0019
17	20	Biased	3.5581	3.552	-0.0061
18	20	Unbiased	3.5659	3.5649	-0.001
19	20	Biased	3.5711	3.572	0.0009
20	50	Unbiased	3.5671	3.5671	0
21	0	Correlation	3.5649	3.5649	0
22	50	Unbiased	3.5609	3.5591	-0.0018
23	0	Correlation	3.569	3.569	0
24	20	Biased	3.5779	3.5739	-0.004
26	50	Biased	3.556	3.547	-0.009
27	30	Unbiased	3.564	3.564	0
28	30	Biased	3.5529	3.5461	-0.0068
29	30	Unbiased	3.5609	3.564	0.0031
30	20	Biased	3.5529	3.547	-0.0059
31	30	Unbiased	3.556	3.5569	0.0009
33	30	Biased	3.564	3.5541	-0.0099
34	50	Unbiased	3.568	3.5739	0.0059
35	20	Unbiased	3.5671	3.569	0.0019
41	30	Biased	3.5631	3.5649	0.0018

Test Statistics (V)

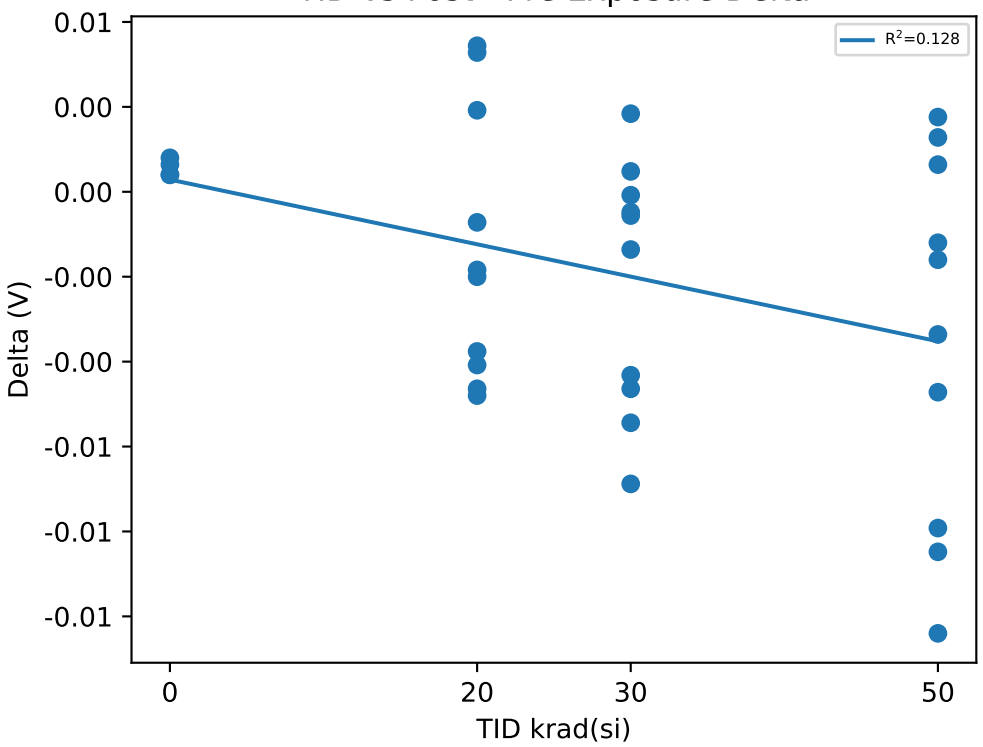
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.5609	3.5645	3.569	0.0034316	3.5609	3.5647	3.569	0.0033397	0	0.000225	0.0009	0.00045
20	3.5501	3.5656	3.5801	0.010533	3.547	3.5646	3.5819	0.012149	-0.0061	-0.00107	0.0019	0.0031847
30	3.5529	3.5636	3.5801	0.0071453	3.5461	3.561	3.5779	0.0083244	-0.0099	-0.00258	0.0031	0.0043949
50	3.552	3.5642	3.5819	0.010278	3.5439	3.5592	3.5841	0.013639	-0.013	-0.00499	0.0059	0.0075624

Device Test: 17.22 UVLO|VIN_RISE/VIN/4.5/4.5/0/1000/4.5/1MHz//@VIN_UVLO_RISE

TID vs Result Stats



TID vs Post - Pre Exposure Delta



Test Results (Lower Limit = 3.85, Upper Limit = 4.15 (V))

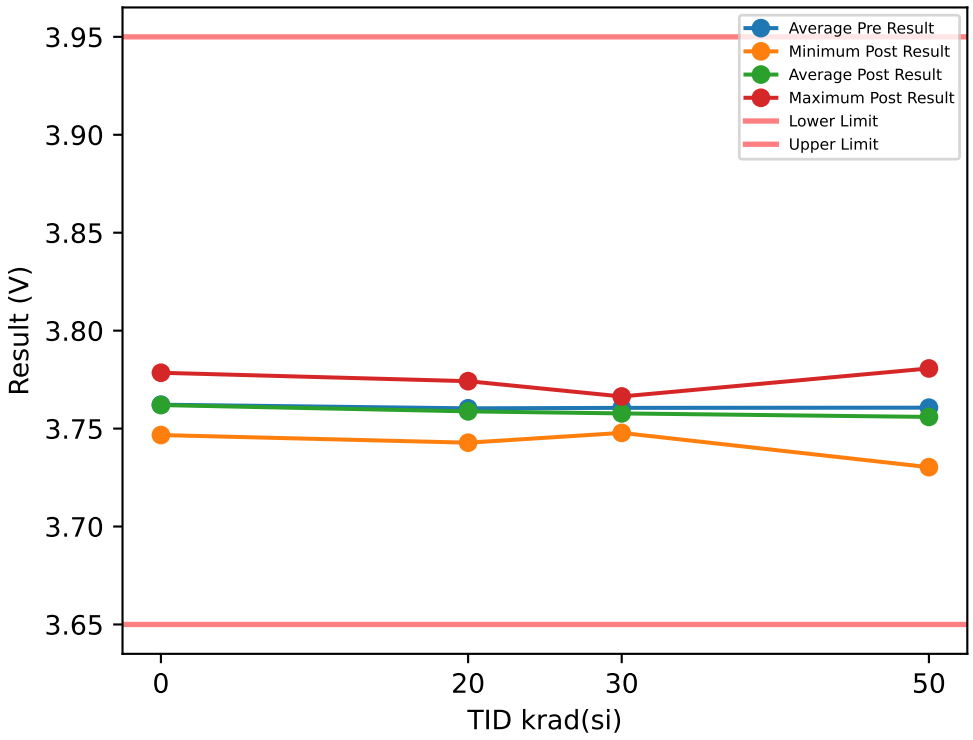
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	3.9714	3.9655	-0.0059
2	20	Unbiased	3.9605	3.9646	0.0041
3	50	Biased	3.9476	3.9346	-0.013
4	30	Unbiased	3.9649	3.9642	-0.0007
5	50	Unbiased	3.9845	3.9853	0.0008
6	30	Biased	3.9664	3.9606	-0.0058
7	50	Biased	3.9698	3.9599	-0.0099
8	30	Unbiased	3.969	3.9684	-0.0006
9	20	Unbiased	3.9636	3.9679	0.0043
10	50	Biased	3.9577	3.9471	-0.0106
11	30	Biased	3.9541	3.9487	-0.0054
12	0	Correlation	3.9765	3.9775	0.001
13	0	Correlation	3.9835	3.9843	0.0008
14	50	Unbiased	3.9714	3.9736	0.0022
15	20	Biased	3.9688	3.9665	-0.0023
16	20	Unbiased	3.9634	3.9609	-0.0025
17	20	Biased	3.9514	3.9463	-0.0051
18	20	Unbiased	3.9648	3.9588	-0.006
19	20	Biased	3.9644	3.9586	-0.0058
20	50	Unbiased	3.964	3.962	-0.002
21	0	Correlation	3.9539	3.9544	0.0005
22	50	Unbiased	3.9445	3.943	-0.0015
23	0	Correlation	3.9526	3.9531	0.0005
24	20	Biased	3.9815	3.9806	-0.0009
26	50	Biased	3.9617	3.9575	-0.0042
27	30	Unbiased	3.9598	3.953	-0.0068
28	30	Biased	3.9606	3.9605	-0.0001
29	30	Unbiased	3.9573	3.9596	0.0023
30	20	Biased	3.9552	3.9505	-0.0047
31	30	Unbiased	3.9591	3.9597	0.0006
33	30	Biased	3.9742	3.9656	-0.0086
34	50	Unbiased	3.9692	3.9708	0.0016
35	20	Unbiased	3.9698	3.9722	0.0024
41	30	Biased	3.9676	3.9659	-0.0017

Test Statistics (V)

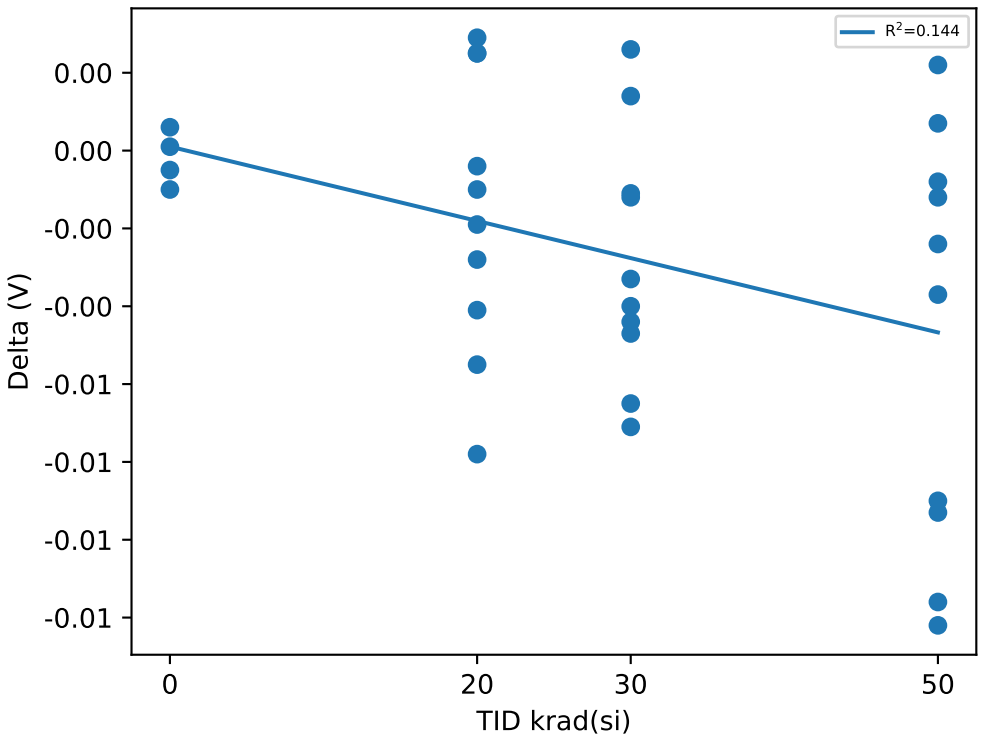
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.9526	3.9666	3.9835	0.015715	3.9531	3.9673	3.9843	0.015928	0.0005	0.0007	0.001	0.00024495
20	3.9514	3.9643	3.9815	0.0082431	3.9463	3.9627	3.9806	0.010049	-0.006	-0.00165	0.0043	0.003999
30	3.9541	3.9633	3.9742	0.0061444	3.9487	3.9606	3.9684	0.0060376	-0.0086	-0.00268	0.0023	0.0036602
50	3.9445	3.9642	3.9845	0.011946	3.9346	3.9599	3.9853	0.015212	-0.013	-0.00425	0.0022	0.0054312

Device Test: 17.23 UVLO|VIN_FALL/VIN/4.5/4.5/0/1000/4.5/1MHz//@VIN_UVLO_FALL

TID vs Result Stats



TID vs Post - Pre Exposure Delta



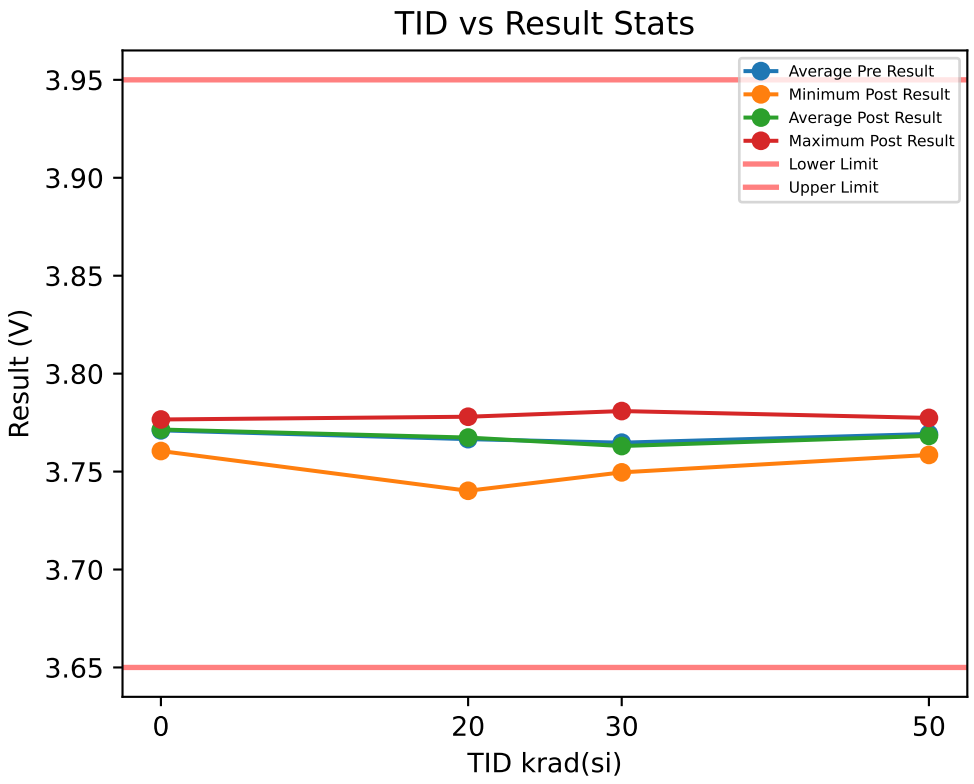
Test Results (Lower Limit = 3.65, Upper Limit = 3.95 (V))

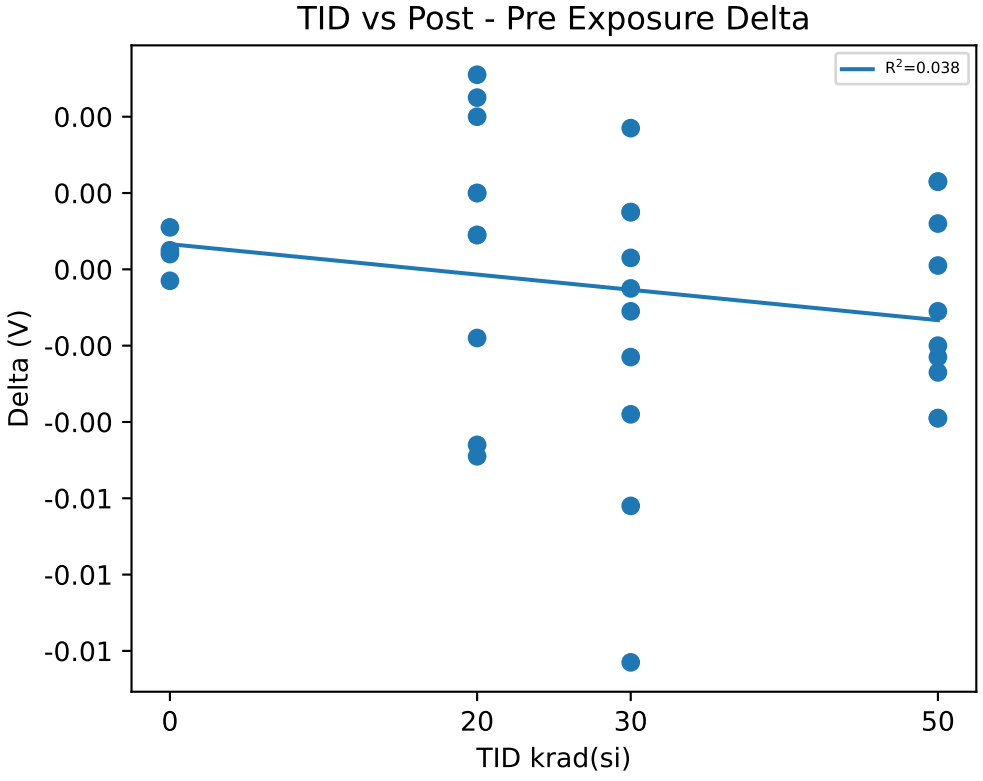
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	3.7684	3.766	-0.0024
2	20	Unbiased	3.7588	3.7613	0.0025
3	50	Biased	3.7425	3.7303	-0.0122
4	30	Unbiased	3.7561	3.755	-0.0011
5	50	Unbiased	3.78	3.7807	0.0007
6	30	Biased	3.7659	3.7588	-0.0071
7	50	Biased	3.7644	3.7554	-0.009
8	30	Unbiased	3.7676	3.7664	-0.0012
9	20	Unbiased	3.7609	3.7634	0.0025
10	50	Biased	3.7588	3.7472	-0.0116
11	30	Biased	3.7525	3.7478	-0.0047
12	0	Correlation	3.772	3.7726	0.0006
13	0	Correlation	3.779	3.7785	-0.0005
14	50	Unbiased	3.7647	3.7669	0.0022
15	20	Biased	3.7616	3.7597	-0.0019
16	20	Unbiased	3.758	3.757	-0.001
17	20	Biased	3.75	3.7445	-0.0055
18	20	Unbiased	3.7584	3.758	-0.0004
19	20	Biased	3.7635	3.7594	-0.0041
20	50	Unbiased	3.7608	3.76	-0.0008
21	0	Correlation	3.7512	3.7502	-0.001
22	50	Unbiased	3.745	3.7413	-0.0037
23	0	Correlation	3.7466	3.7467	0.0001
24	20	Biased	3.777	3.7742	-0.0028
26	50	Biased	3.7588	3.7495	-0.0093
27	30	Unbiased	3.7569	3.7525	-0.0044
28	30	Biased	3.7608	3.7575	-0.0033
29	30	Unbiased	3.7537	3.7563	0.0026
30	20	Biased	3.7506	3.7428	-0.0078
31	30	Unbiased	3.7553	3.7567	0.0014
33	30	Biased	3.7709	3.7644	-0.0065
34	50	Unbiased	3.7634	3.7622	-0.0012
35	20	Unbiased	3.7647	3.7676	0.0029
41	30	Biased	3.7661	3.7621	-0.004

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.7466	3.7622	3.779	0.015734	3.7467	3.762	3.7785	0.015895	-0.001	-0.0002	0.0006	0.00069761
20	3.75	3.7603	3.777	0.0076146	3.7428	3.7588	3.7742	0.0094725	-0.0078	-0.00156	0.0029	0.0036068
30	3.7525	3.7606	3.7709	0.006572	3.7478	3.7578	3.7664	0.0055424	-0.0071	-0.00283	0.0026	0.0032021
50	3.7425	3.7607	3.78	0.01082	3.7303	3.7559	3.7807	0.014453	-0.0122	-0.00473	0.0022	0.0053127

Device Test: 17.25 UVLO|VLDO_RISE/VLDO/4.5/4.5/0/1000/4.5/1MHz//@VLDO_UVLO_RISE





Test Results (Lower Limit = 3.65, Upper Limit = 3.95 (V))

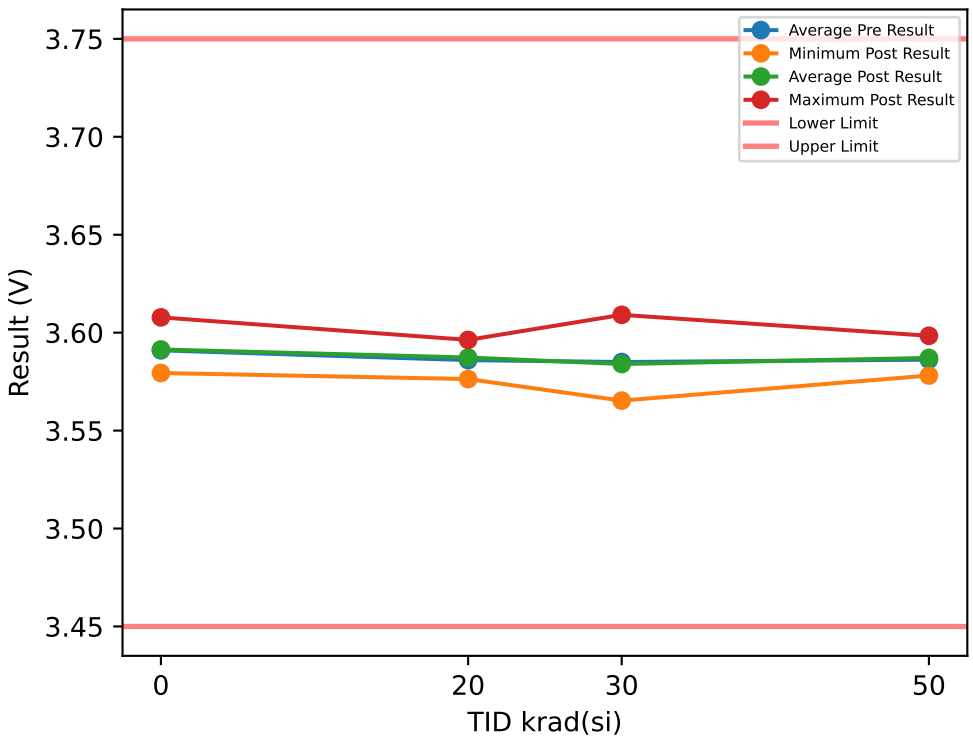
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	3.7775	3.7748	-0.0027
2	20	Unbiased	3.7679	3.7688	0.0009
3	50	Biased	3.764	3.762	-0.002
4	30	Unbiased	3.7517	3.7506	-0.0011
5	50	Unbiased	3.7716	3.7677	-0.0039
6	30	Biased	3.7732	3.7727	-0.0005
7	50	Biased	3.7662	3.7651	-0.0011
8	30	Unbiased	3.7683	3.772	0.0037
9	20	Unbiased	3.7732	3.7777	0.0045
10	50	Biased	3.771	3.7687	-0.0023
11	30	Biased	3.7534	3.7496	-0.0038
12	0	Correlation	3.7751	3.7755	0.0004
13	0	Correlation	3.7769	3.7766	-0.0003
14	50	Unbiased	3.7773	3.7774	0.0001
15	20	Biased	3.7609	3.7618	0.0009
16	20	Unbiased	3.7798	3.778	-0.0018
17	20	Biased	3.7451	3.7402	-0.0049
18	20	Unbiased	3.7648	3.7699	0.0051
19	20	Biased	3.7703	3.7723	0.002
20	50	Unbiased	3.7695	3.7718	0.0023
21	0	Correlation	3.7722	3.7733	0.0011
22	50	Unbiased	3.7651	3.7612	-0.0039
23	0	Correlation	3.76	3.7605	0.0005
24	20	Biased	3.7757	3.7777	0.002
26	50	Biased	3.7726	3.7749	0.0023
27	30	Unbiased	3.7681	3.7684	0.0003
28	30	Biased	3.7486	3.7501	0.0015
29	30	Unbiased	3.7816	3.7713	-0.0103
30	20	Biased	3.757	3.7524	-0.0046
31	30	Unbiased	3.7565	3.758	0.0015
33	30	Biased	3.7832	3.7809	-0.0023
34	50	Unbiased	3.7573	3.7585	0.0012
35	20	Unbiased	3.7709	3.7749	0.004
41	30	Biased	3.763	3.7568	-0.0062

Test Statistics (V)

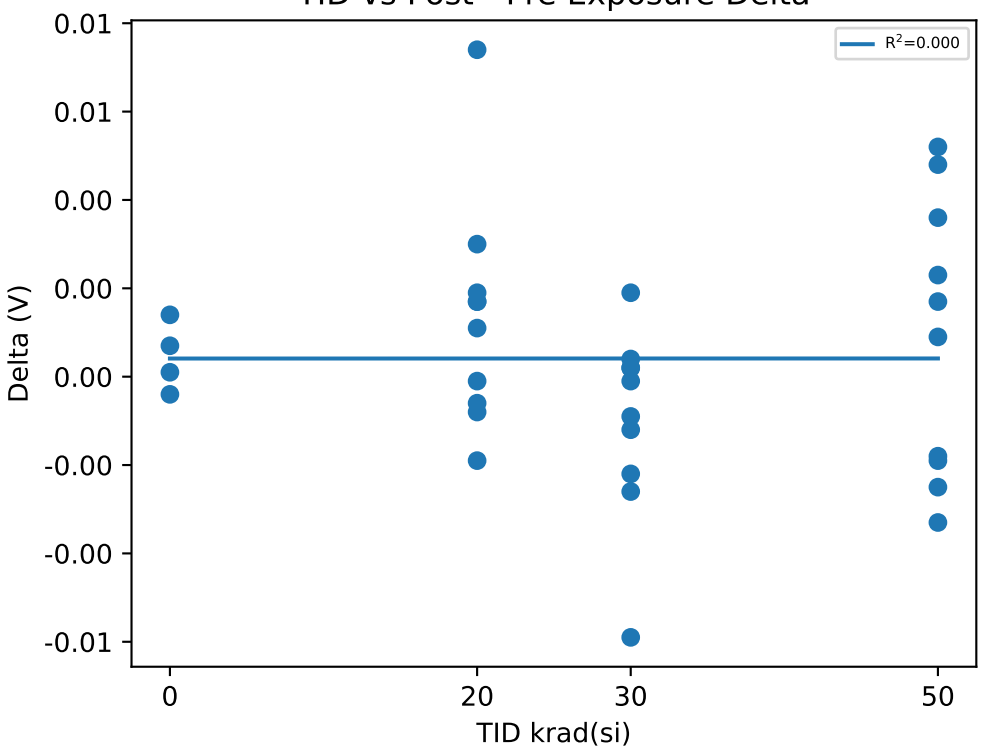
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.76	3.771	3.7769	0.0076169	3.7605	3.7715	3.7766	0.0074442	-0.0003	0.000425	0.0011	0.00057373
20	3.7451	3.7666	3.7798	0.010136	3.7402	3.7674	3.778	0.012513	-0.0049	0.00081	0.0051	0.0035548
30	3.7486	3.7648	3.7832	0.01225	3.7496	3.763	3.7809	0.011337	-0.0103	-0.00172	0.0037	0.0041421
50	3.7573	3.7692	3.7775	0.0062326	3.7585	3.7682	3.7774	0.0064781	-0.0039	-0.001	0.0023	0.0023627

Device Test: 17.26 UVLO|VLDO_FALL/VLDO/4.5/4.5/0/1000/4.5/1MHz//@VLDO_UVLO_FALL

TID vs Result Stats



TID vs Post - Pre Exposure Delta



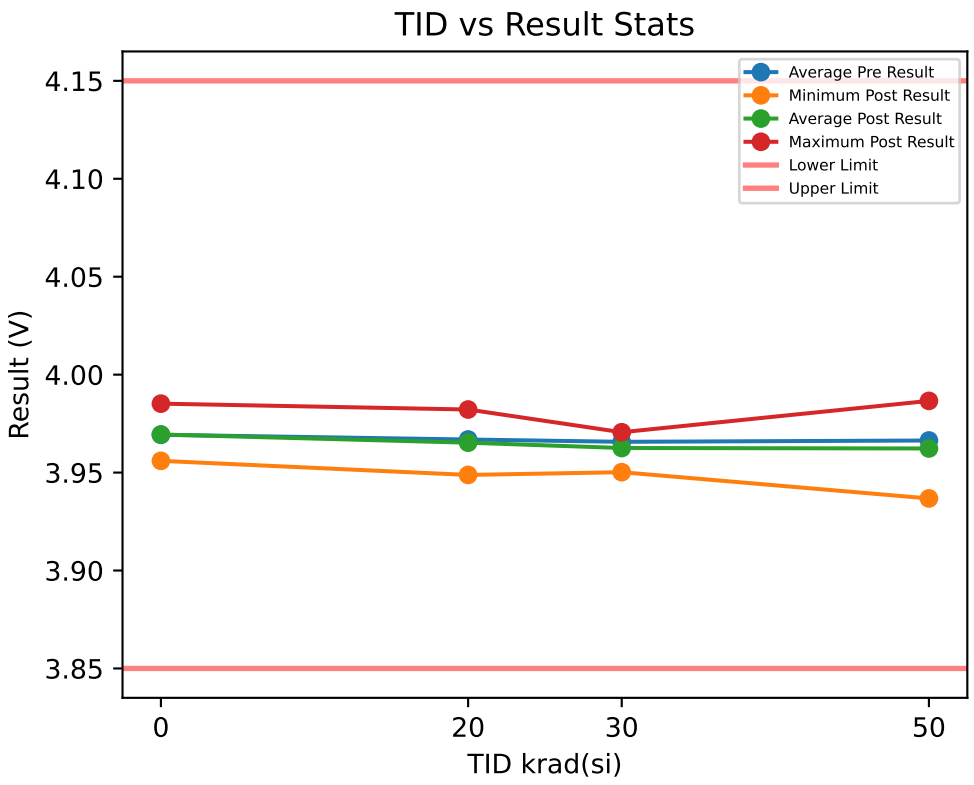
Test Results (Lower Limit = 3.45, Upper Limit = 3.75 (V))

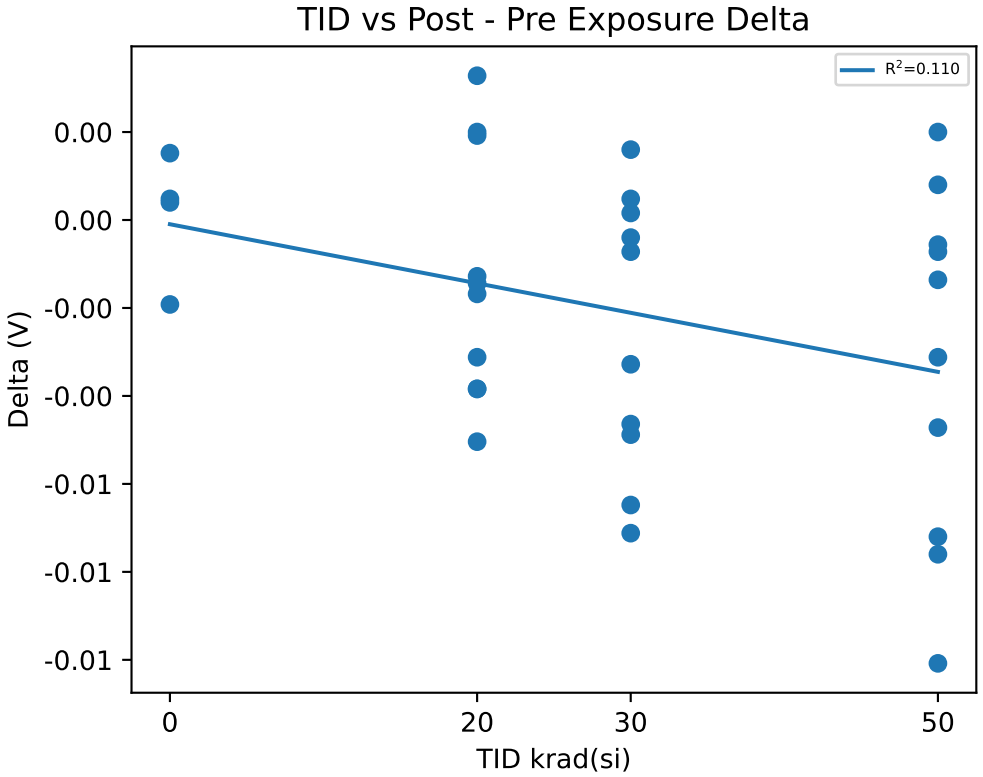
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	3.5936	3.5984	0.0048
2	20	Unbiased	3.5794	3.5775	-0.0019
3	50	Biased	3.5817	3.5784	-0.0033
4	30	Unbiased	3.5825	3.5813	-0.0012
5	50	Unbiased	3.5877	3.5894	0.0017
6	30	Biased	3.5897	3.5875	-0.0022
7	50	Biased	3.5848	3.59	0.0052
8	30	Unbiased	3.585	3.5841	-0.0009
9	20	Unbiased	3.5833	3.5907	0.0074
10	50	Biased	3.5922	3.5903	-0.0019
11	30	Biased	3.5783	3.5785	0.0002
12	0	Correlation	3.5881	3.5882	0.0001
13	0	Correlation	3.6064	3.6078	0.0014
14	50	Unbiased	3.589	3.5913	0.0023
15	20	Biased	3.5861	3.5853	-0.0008
16	20	Unbiased	3.5921	3.5938	0.0017
17	20	Biased	3.5733	3.5763	0.003
18	20	Unbiased	3.5862	3.5856	-0.0006
19	20	Biased	3.5942	3.5953	0.0011
20	50	Unbiased	3.5821	3.5857	0.0036
21	0	Correlation	3.5896	3.5903	0.0007
22	50	Unbiased	3.5884	3.5866	-0.0018
23	0	Correlation	3.5798	3.5794	-0.0004
24	20	Biased	3.5946	3.5963	0.0017
26	50	Biased	3.5853	3.5828	-0.0025
27	30	Unbiased	3.5889	3.5863	-0.0026
28	30	Biased	3.5712	3.5653	-0.0059
29	30	Unbiased	3.5883	3.5887	0.0004
30	20	Biased	3.5794	3.5813	0.0019
31	30	Unbiased	3.5839	3.5841	0.0002
33	30	Biased	3.6092	3.6091	-0.0001
34	50	Unbiased	3.5772	3.5781	0.0009
35	20	Unbiased	3.5911	3.591	-0.0001
41	30	Biased	3.573	3.5749	0.0019

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.5798	3.591	3.6064	0.01115	3.5794	3.5914	3.6078	0.011894	-0.0004	0.00045	0.0014	0.00077675
20	3.5733	3.586	3.5946	0.0071505	3.5763	3.5873	3.5963	0.0072451	-0.0019	0.00134	0.0074	0.0026039
30	3.5712	3.585	3.6092	0.010649	3.5653	3.584	3.6091	0.011253	-0.0059	-0.00102	0.0019	0.0021632
50	3.5772	3.5862	3.5936	0.0050169	3.5781	3.5871	3.5984	0.0062063	-0.0033	0.0009	0.0052	0.0031255

Device Test: 17.4 UVLO|VIN_RISE/VIN/4.5/4.5/0/1000/4.5/100kHz//@VIN_UVLO_RISE





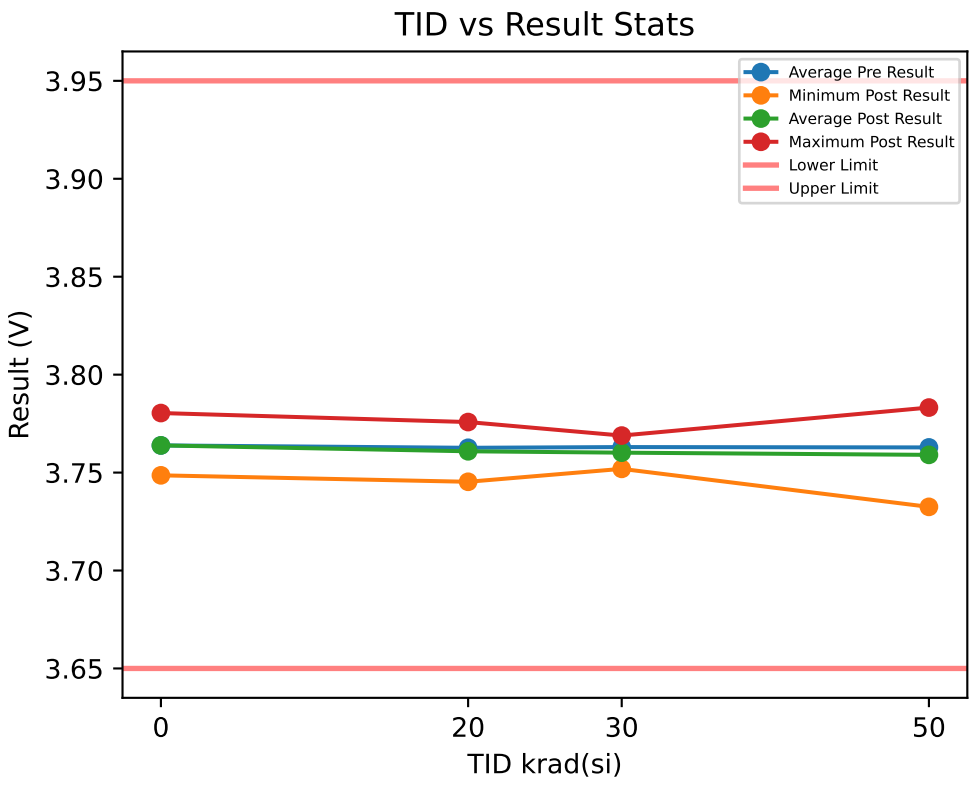
Test Results (Lower Limit = 3.85, Upper Limit = 4.15 (V))

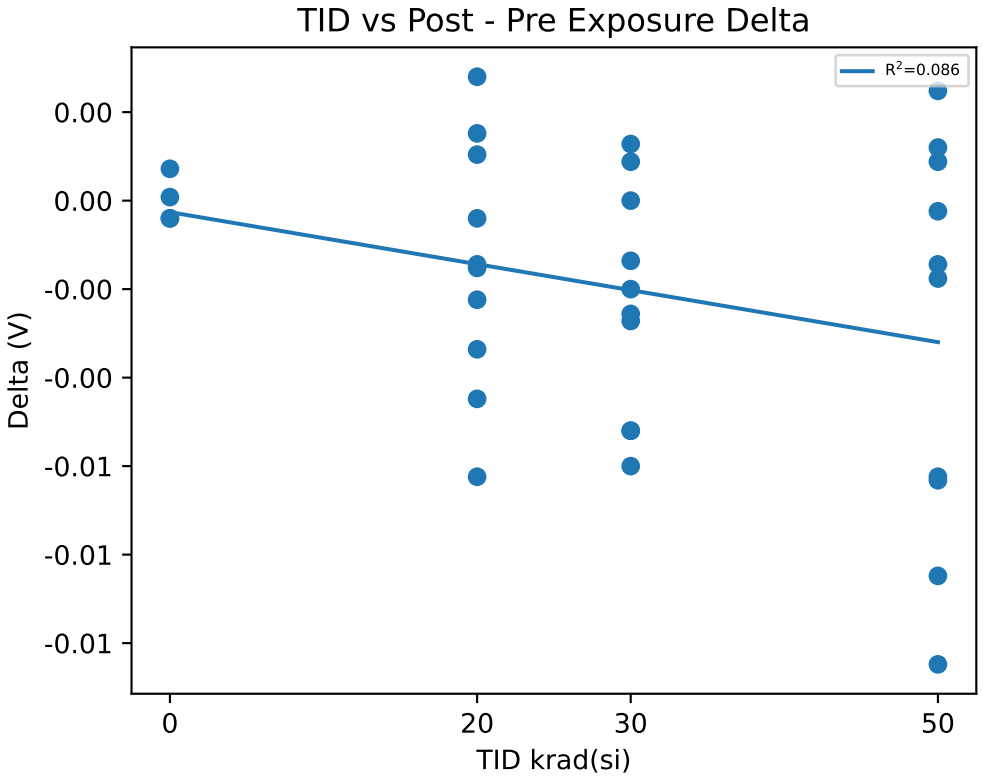
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	3.9736	3.9677	-0.0059
2	20	Unbiased	3.9633	3.9658	0.0025
3	50	Biased	3.9494	3.9368	-0.0126
4	30	Unbiased	3.9674	3.9633	-0.0041
5	50	Unbiased	3.9873	3.9866	-0.0007
6	30	Biased	3.9686	3.9628	-0.0058
7	50	Biased	3.9716	3.9621	-0.0095
8	30	Unbiased	3.9715	3.9706	-0.0009
9	20	Unbiased	3.9667	3.9708	0.0041
10	50	Biased	3.9595	3.9505	-0.009
11	30	Biased	3.9563	3.9502	-0.0061
12	0	Correlation	3.9781	3.98	0.0019
13	0	Correlation	3.9876	3.9852	-0.0024
14	50	Unbiased	3.9739	3.9764	0.0025
15	20	Biased	3.9713	3.9697	-0.0016
16	20	Unbiased	3.9662	3.9644	-0.0018
17	20	Biased	3.9536	3.9488	-0.0048
18	20	Unbiased	3.9676	3.9613	-0.0063
19	20	Biased	3.9663	3.9615	-0.0048
20	50	Unbiased	3.9665	3.9648	-0.0017
21	0	Correlation	3.9561	3.9566	0.0005
22	50	Unbiased	3.9467	3.9458	-0.0009
23	0	Correlation	3.9554	3.956	0.0006
24	20	Biased	3.9843	3.9822	-0.0021
26	50	Biased	3.9636	3.9597	-0.0039
27	30	Unbiased	3.9626	3.9545	-0.0081
28	30	Biased	3.9631	3.9633	0.0002
29	30	Unbiased	3.9598	3.9618	0.002
30	20	Biased	3.9573	3.9534	-0.0039
31	30	Unbiased	3.9616	3.9622	0.0006
33	30	Biased	3.977	3.9681	-0.0089
34	50	Unbiased	3.9717	3.9727	0.001
35	20	Unbiased	3.9723	3.9747	0.0024
41	30	Biased	3.9692	3.9687	-0.0005

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.9554	3.9693	3.9876	0.016122	3.956	3.9695	3.9852	0.015334	-0.0024	0.00015	0.0019	0.0018157
20	3.9536	3.9669	3.9843	0.0083975	3.9488	3.9653	3.9822	0.0098258	-0.0063	-0.00163	0.0041	0.0035503
30	3.9563	3.9657	3.977	0.0061575	3.9502	3.9626	3.9706	0.0062594	-0.0089	-0.00316	0.002	0.003917
50	3.9467	3.9664	3.9873	0.012168	3.9368	3.9623	3.9866	0.014912	-0.0126	-0.00407	0.0025	0.0050091

Device Test: 17.5 UVLO|VIN_FALL/VIN/4.5/4.5/0/1000/4.5/100kHz//@VIN_UVLO_FALL





Test Results (Lower Limit = 3.65, Upper Limit = 3.95 (V))

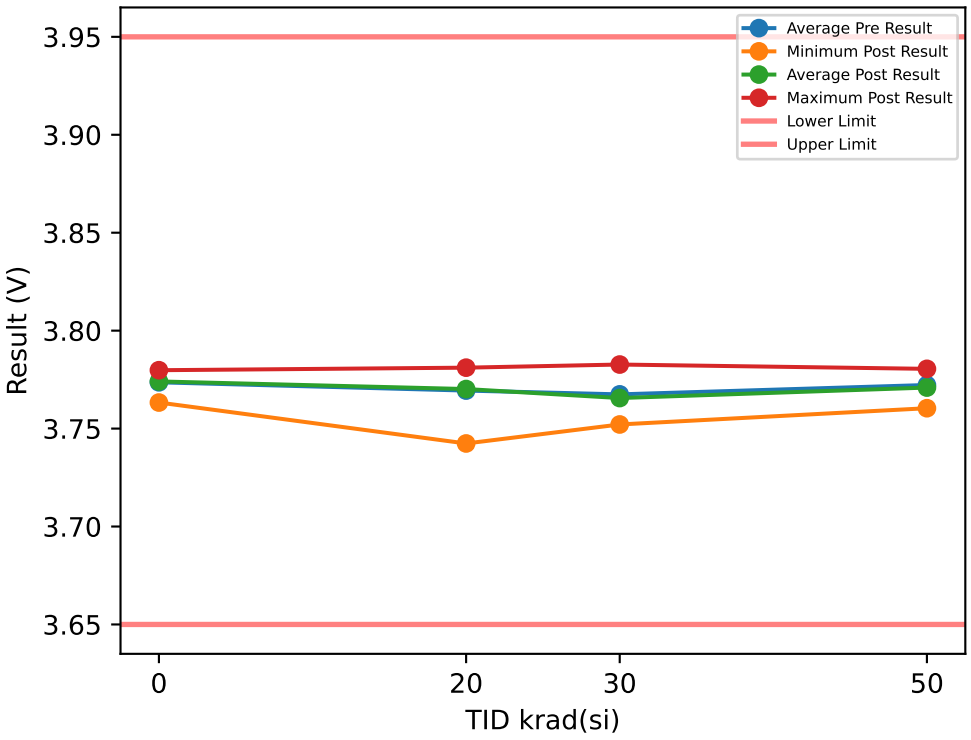
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	3.7709	3.7691	-0.0018
2	20	Unbiased	3.7619	3.7632	0.0013
3	50	Biased	3.7456	3.7325	-0.0131
4	30	Unbiased	3.7586	3.7569	-0.0017
5	50	Unbiased	3.7821	3.7832	0.0011
6	30	Biased	3.7691	3.7616	-0.0075
7	50	Biased	3.7666	3.7588	-0.0078
8	30	Unbiased	3.7689	3.7689	0
9	20	Unbiased	3.764	3.7659	0.0019
10	50	Biased	3.7591	3.7485	-0.0106
11	30	Biased	3.7553	3.7519	-0.0034
12	0	Correlation	3.7739	3.7748	0.0009
13	0	Correlation	3.7809	3.7804	-0.0005
14	50	Unbiased	3.7669	3.77	0.0031
15	20	Biased	3.7644	3.7616	-0.0028
16	20	Unbiased	3.7608	3.7589	-0.0019
17	20	Biased	3.7519	3.7477	-0.0042
18	20	Unbiased	3.76	3.7595	-0.0005
19	20	Biased	3.7666	3.761	-0.0056
20	50	Unbiased	3.7626	3.7641	0.0015
21	0	Correlation	3.7522	3.7517	-0.0005
22	50	Unbiased	3.7472	3.745	-0.0022
23	0	Correlation	3.7485	3.7486	0.0001
24	20	Biased	3.7776	3.7758	-0.0018
26	50	Biased	3.7606	3.7527	-0.0079
27	30	Unbiased	3.7575	3.755	-0.0025
28	30	Biased	3.7636	3.7604	-0.0032
29	30	Unbiased	3.7572	3.7588	0.0016
30	20	Biased	3.7531	3.7453	-0.0078
31	30	Unbiased	3.7581	3.7592	0.0011
33	30	Biased	3.7737	3.7672	-0.0065
34	50	Unbiased	3.7669	3.7666	-0.0003
35	20	Unbiased	3.7663	3.7698	0.0035
41	30	Biased	3.7683	3.7618	-0.0065

Test Statistics (V)

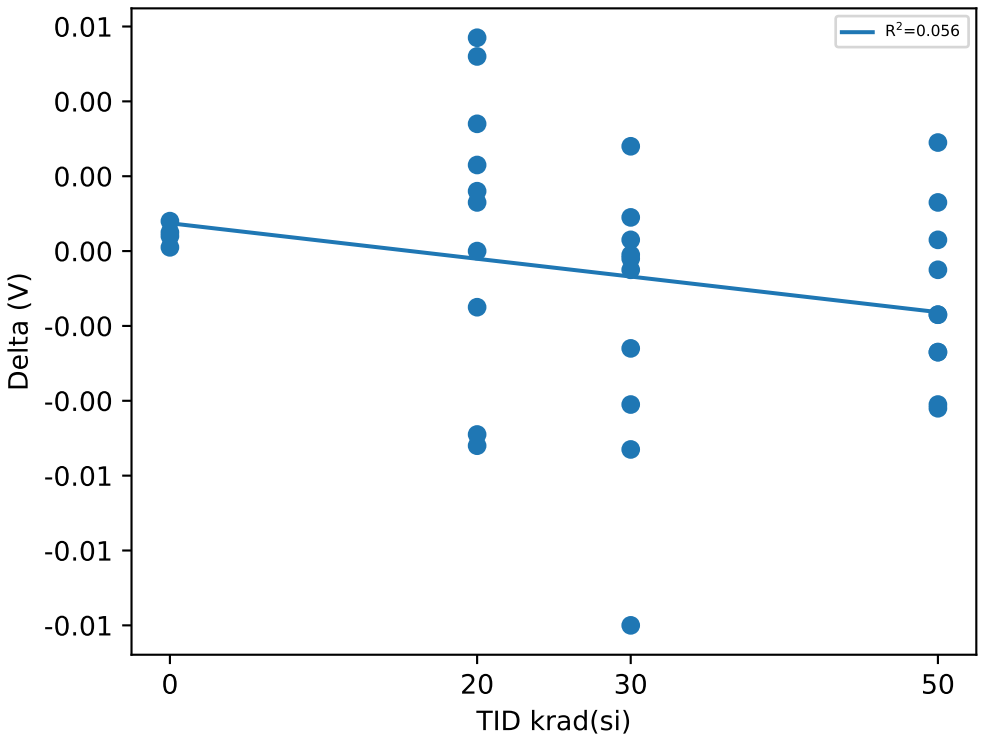
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.7485	3.7639	3.7809	0.015948	3.7486	3.7639	3.7804	0.016062	-0.0005	1.1102e-16	0.0009	0.00066332
20	3.7519	3.7627	3.7776	0.0072655	3.7453	3.7609	3.7758	0.0091625	-0.0078	-0.00179	0.0035	0.0035006
30	3.7553	3.763	3.7737	0.0065107	3.7519	3.7602	3.7689	0.0051534	-0.0075	-0.00286	0.0016	0.003226
50	3.7456	3.7629	3.7821	0.01077	3.7325	3.759	3.7832	0.014684	-0.0131	-0.0038	0.0031	0.005618

Device Test: 17.7 UVLO|VLDO_RISE/VLDO/4.5/4.5/0/1000/4.5/100kHz//@VLDO_UVLO_RISE

TID vs Result Stats



TID vs Post - Pre Exposure Delta



Test Results (Lower Limit = 3.65, Upper Limit = 3.95 (V))

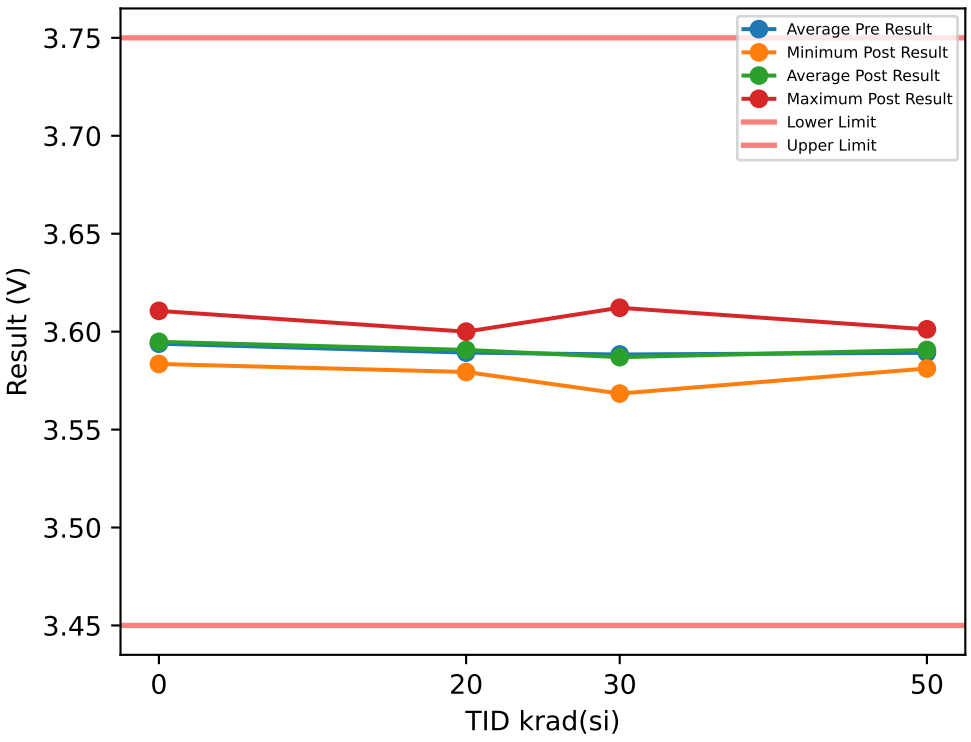
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	3.7807	3.7766	-0.0041
2	20	Unbiased	3.7707	3.772	0.0013
3	50	Biased	3.7668	3.7651	-0.0017
4	30	Unbiased	3.7536	3.7531	-0.0005
5	50	Unbiased	3.7747	3.7705	-0.0042
6	30	Biased	3.7757	3.7755	-0.0002
7	50	Biased	3.7697	3.767	-0.0027
8	30	Unbiased	3.7714	3.7742	0.0028
9	20	Unbiased	3.7757	3.7809	0.0052
10	50	Biased	3.7735	3.7718	-0.0017
11	30	Biased	3.7562	3.7521	-0.0041
12	0	Correlation	3.7776	3.7777	0.0001
13	0	Correlation	3.7794	3.7798	0.0004
14	50	Unbiased	3.781	3.7805	-0.0005
15	20	Biased	3.764	3.764	0
16	20	Unbiased	3.7826	3.7811	-0.0015
17	20	Biased	3.7476	3.7424	-0.0052
18	20	Unbiased	3.7673	3.773	0.0057
19	20	Biased	3.7734	3.7757	0.0023
20	50	Unbiased	3.7739	3.7752	0.0013
21	0	Correlation	3.7747	3.7755	0.0008
22	50	Unbiased	3.7673	3.7646	-0.0027
23	0	Correlation	3.7628	3.7633	0.0005
24	20	Biased	3.7786	3.7802	0.0016
26	50	Biased	3.7748	3.7777	0.0029
27	30	Unbiased	3.7712	3.7715	0.0003
28	30	Biased	3.7526	3.7535	0.0009
29	30	Unbiased	3.7835	3.7735	-0.01
30	20	Biased	3.7601	3.7552	-0.0049
31	30	Unbiased	3.7603	3.7602	-0.0001
33	30	Biased	3.7853	3.7827	-0.0026
34	50	Unbiased	3.7601	3.7604	0.0003
35	20	Unbiased	3.774	3.7774	0.0034
41	30	Biased	3.7649	3.7596	-0.0053

Test Statistics (V)

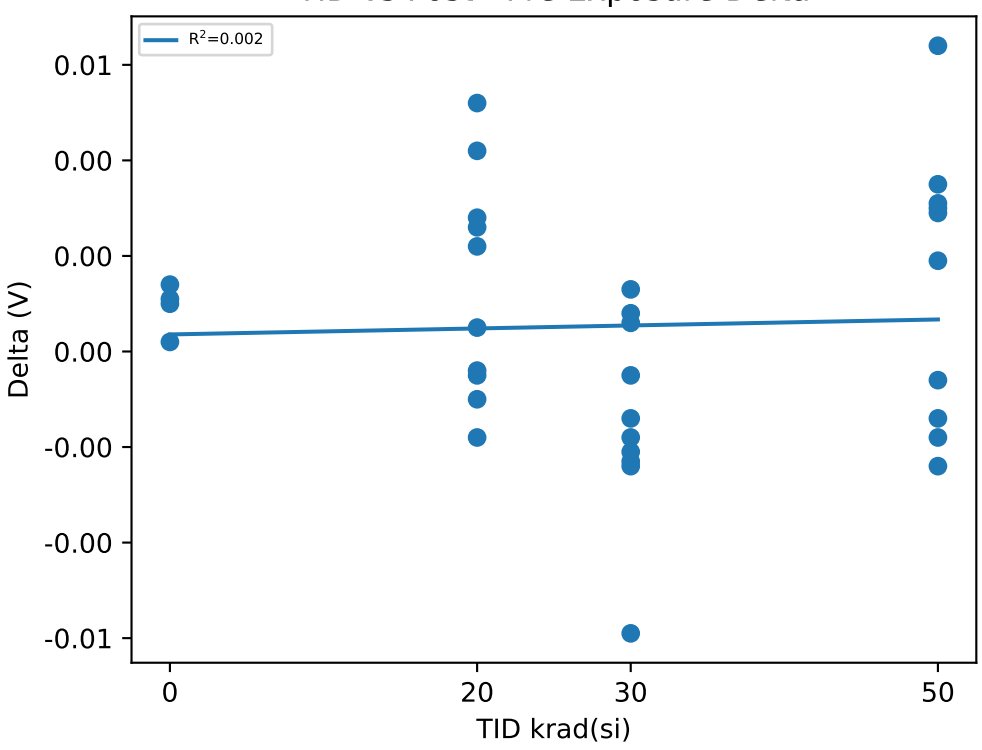
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.7628	3.7736	3.7794	0.0074719	3.7633	3.7741	3.7798	0.0073948	0.0001	0.00045	0.0008	0.00028868
20	3.7476	3.7694	3.7826	0.01018	3.7424	3.7702	3.7811	0.012749	-0.0052	0.00079	0.0057	0.0037667
30	3.7526	3.7675	3.7853	0.011881	3.7521	3.7656	3.7827	0.011114	-0.01	-0.00188	0.0028	0.0037321
50	3.7601	3.7722	3.781	0.0064385	3.7604	3.7709	3.7805	0.0065754	-0.0042	-0.00131	0.0029	0.0023115

Device Test: 17.8 UVLO|VLDO_FALL/VLDO/4.5/4.5/0/1000/4.5/100kHz//@VLDO_UVLO_FALL

TID vs Result Stats



TID vs Post - Pre Exposure Delta



Test Results (Lower Limit = 3.45, Upper Limit = 3.75 (V))

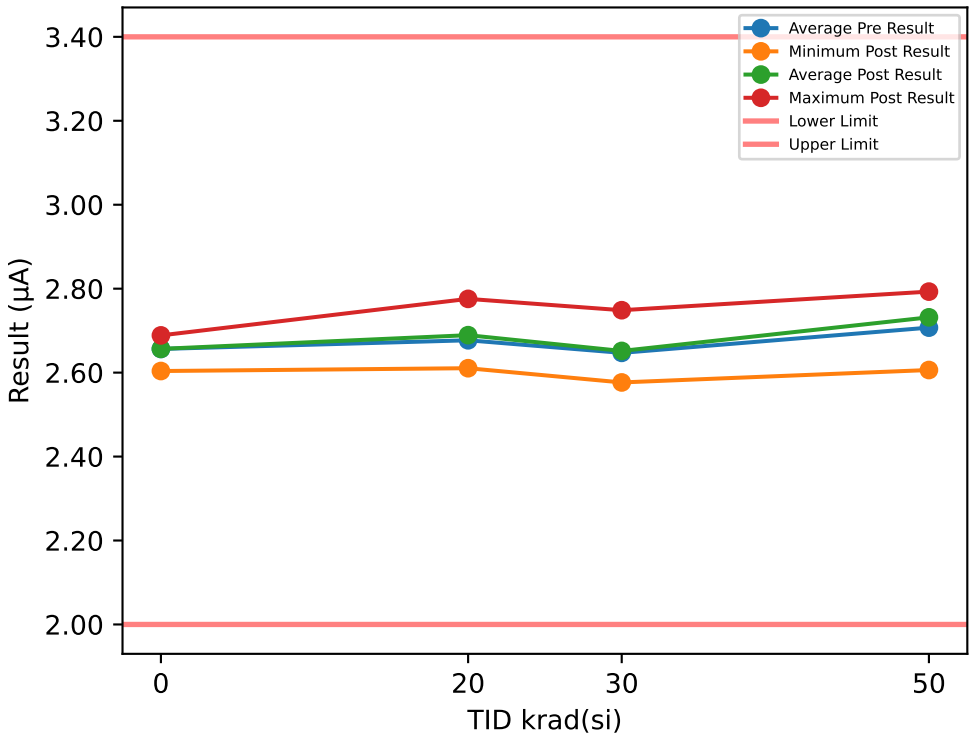
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	3.5977	3.6012	0.0035
2	20	Unbiased	3.5812	3.5794	-0.0018
3	50	Biased	3.5826	3.5812	-0.0014
4	30	Unbiased	3.5868	3.5844	-0.0024
5	50	Unbiased	3.5905	3.5935	0.003
6	30	Biased	3.5915	3.5894	-0.0021
7	50	Biased	3.5873	3.5937	0.0064
8	30	Unbiased	3.5893	3.5875	-0.0018
9	20	Unbiased	3.588	3.5932	0.0052
10	50	Biased	3.5956	3.5938	-0.0018
11	30	Biased	3.5823	3.5829	0.0006
12	0	Correlation	3.5903	3.5913	0.001
13	0	Correlation	3.6095	3.6106	0.0011
14	50	Unbiased	3.5922	3.5953	0.0031
15	20	Biased	3.5895	3.5885	-0.001
16	20	Unbiased	3.5962	3.5988	0.0026
17	20	Biased	3.5764	3.5806	0.0042
18	20	Unbiased	3.5893	3.5888	-0.0005
19	20	Biased	3.5979	3.5984	0.0005
20	50	Unbiased	3.5865	3.5894	0.0029
21	0	Correlation	3.5924	3.5938	0.0014
22	50	Unbiased	3.5903	3.5897	-0.0006
23	0	Correlation	3.5833	3.5835	0.0002
24	20	Biased	3.5978	3.6	0.0022
26	50	Biased	3.5887	3.5863	-0.0024
27	30	Unbiased	3.5917	3.5894	-0.0023
28	30	Biased	3.5743	3.5684	-0.0059
29	30	Unbiased	3.5917	3.5912	-0.0005
30	20	Biased	3.5819	3.5847	0.0028
31	30	Unbiased	3.5861	3.5869	0.0008
33	30	Biased	3.6136	3.6122	-0.0014
34	50	Unbiased	3.5806	3.5825	0.0019
35	20	Unbiased	3.5948	3.5944	-0.0004
41	30	Biased	3.5761	3.5774	0.0013

Test Statistics (V)

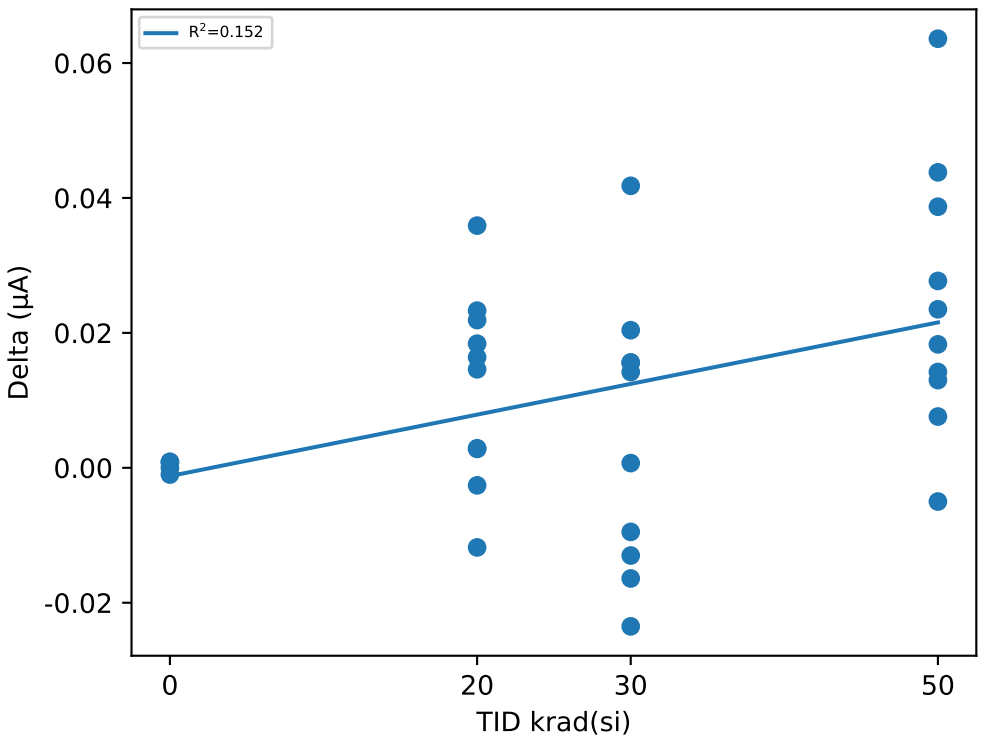
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.5833	3.5939	3.6095	0.011119	3.5835	3.5948	3.6106	0.01141	0.0002	0.000925	0.0014	0.00051235
20	3.5764	3.5893	3.5979	0.0075467	3.5794	3.5907	3.6	0.0074943	-0.0018	0.00138	0.0052	0.0023565
30	3.5743	3.5883	3.6136	0.010865	3.5684	3.587	3.6122	0.011186	-0.0059	-0.00137	0.0013	0.0020987
50	3.5806	3.5892	3.5977	0.0053102	3.5812	3.5907	3.6012	0.0061227	-0.0024	0.00146	0.0064	0.0028644

Device Test: 18.1 CURRENT|SS_0p3V/SS/4.5/4.5/0/1000/4.5/100kHz//@I_SS

TID vs Result Stats



TID vs Post - Pre Exposure Delta



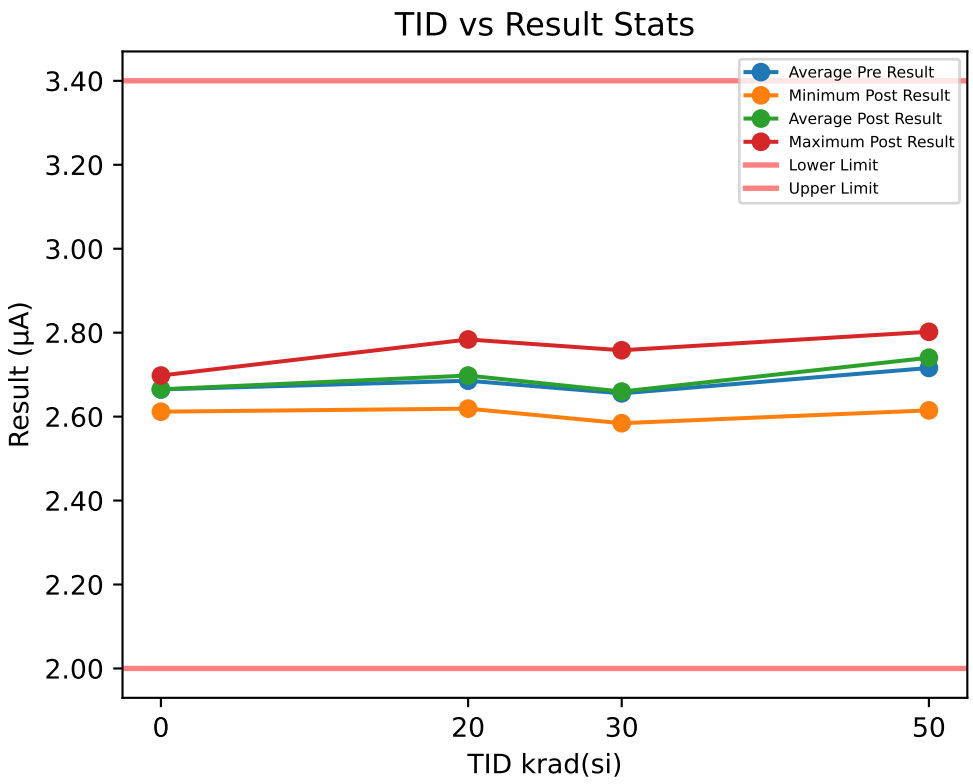
Test Results (Lower Limit = 2.0, Upper Limit = 3.4 (µA))

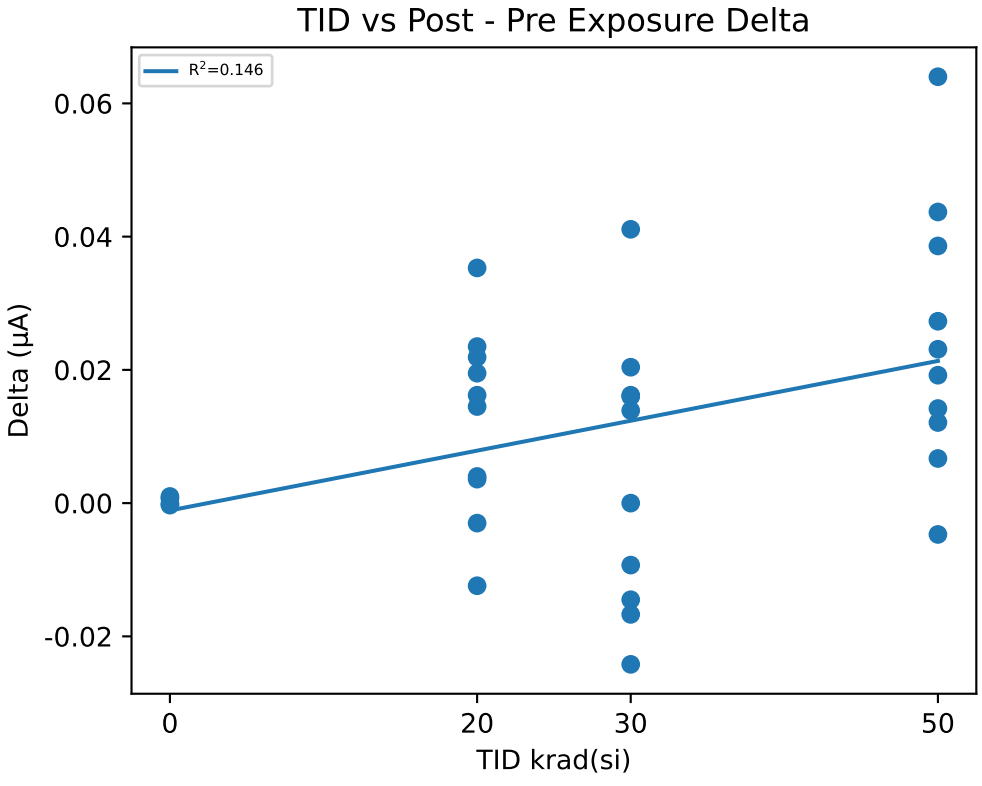
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	2.6959	2.7089	0.013
2	20	Unbiased	2.655	2.6714	0.0164
3	50	Biased	2.6112	2.6062	-0.005
4	30	Unbiased	2.6134	2.629	0.0156
5	50	Unbiased	2.7452	2.7528	0.0076
6	30	Biased	2.6245	2.6449	0.0204
7	50	Biased	2.7294	2.793	0.0636
8	30	Unbiased	2.6293	2.6449	0.0156
9	20	Unbiased	2.5954	2.6313	0.0359
10	50	Biased	2.733	2.7607	0.0277
11	30	Biased	2.6193	2.6335	0.0142
12	0	Correlation	2.6556	2.6556	0
13	0	Correlation	2.6897	2.6887	-0.001
14	50	Unbiased	2.7195	2.743	0.0235
15	20	Biased	2.7494	2.7468	-0.0026
16	20	Unbiased	2.6248	2.6276	0.0028
17	20	Biased	2.7351	2.7584	0.0233
18	20	Unbiased	2.7309	2.7455	0.0146
19	20	Biased	2.664	2.6824	0.0184
20	50	Unbiased	2.7722	2.7905	0.0183
21	0	Correlation	2.6773	2.6782	0.0009
22	50	Unbiased	2.6334	2.6772	0.0438
23	0	Correlation	2.603	2.6038	0.0008
24	20	Biased	2.6397	2.6426	0.0029
26	50	Biased	2.6722	2.7109	0.0387
27	30	Unbiased	2.7651	2.7487	-0.0164
28	30	Biased	2.674	2.6645	-0.0095
29	30	Unbiased	2.6427	2.6297	-0.013
30	20	Biased	2.5886	2.6105	0.0219
31	30	Unbiased	2.6546	2.6553	0.0007
33	30	Biased	2.6478	2.6896	0.0418
34	50	Unbiased	2.7599	2.7741	0.0142
35	20	Unbiased	2.7875	2.7757	-0.0118
41	30	Biased	2.6001	2.5766	-0.0235

Test Statistics (µA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.603	2.6564	2.6897	0.038288	2.6038	2.6566	2.6887	0.037797	-0.001	0.000175	0.0009	0.00088081
20	2.5886	2.677	2.7875	0.069101	2.6105	2.6892	2.7757	0.062034	-0.0118	0.01218	0.0359	0.014184
30	2.6001	2.6471	2.7651	0.046749	2.5766	2.6517	2.7487	0.044827	-0.0235	0.00459	0.0418	0.020336
50	2.6112	2.7072	2.7722	0.053511	2.6062	2.7317	2.793	0.057831	-0.005	0.02454	0.0636	0.019852

Device Test: 18.13 CURRENT|SS_0p3V/SS/14/14/0/1000/5/100kHz//@I_SS





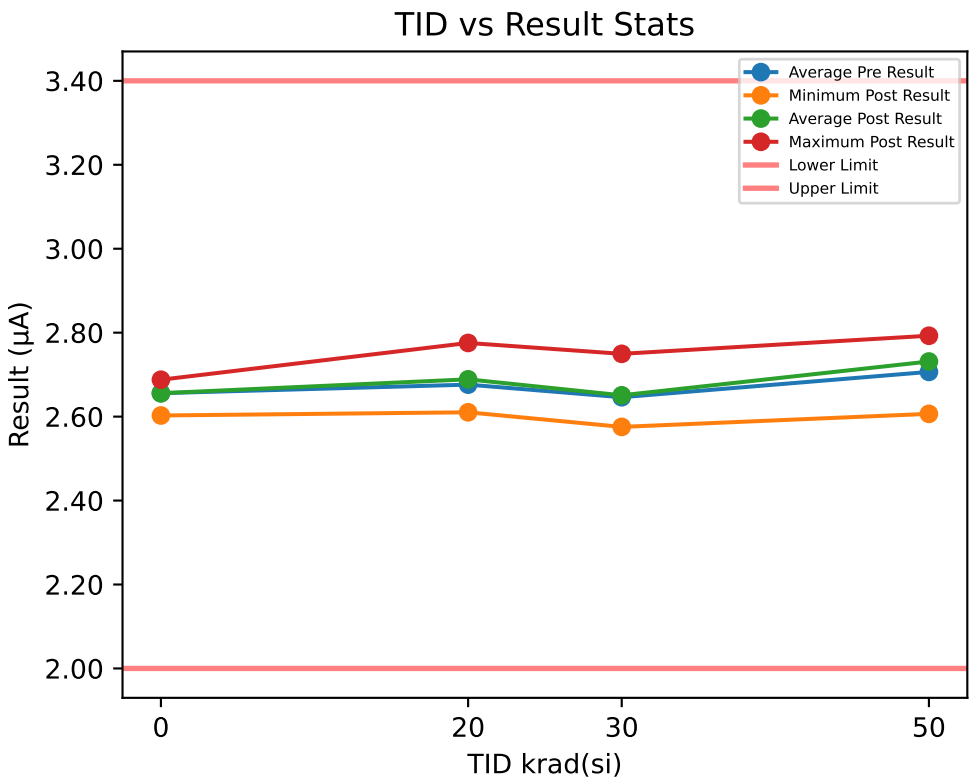
Test Results (Lower Limit = 2.0, Upper Limit = 3.4 (µA))

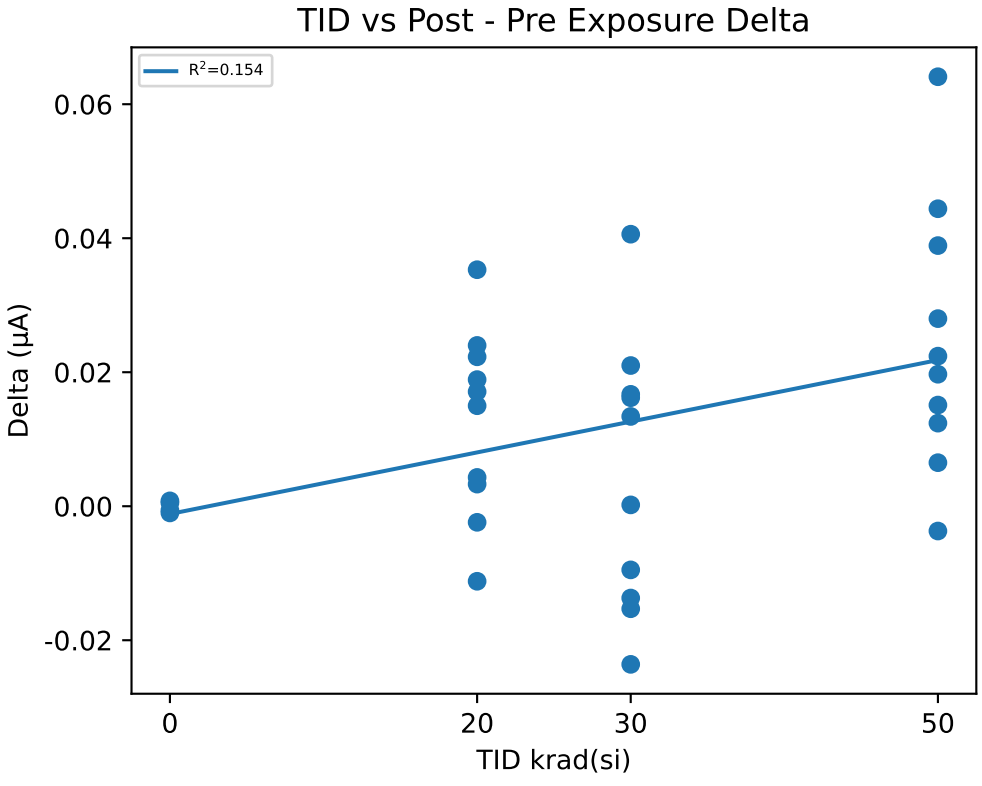
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	2.7046	2.7167	0.0121
2	20	Unbiased	2.6639	2.6801	0.0162
3	50	Biased	2.6196	2.6149	-0.0047
4	30	Unbiased	2.6207	2.6367	0.016
5	50	Unbiased	2.7538	2.7605	0.0067
6	30	Biased	2.6319	2.6523	0.0204
7	50	Biased	2.7381	2.8021	0.064
8	30	Unbiased	2.6374	2.6536	0.0162
9	20	Unbiased	2.6031	2.6384	0.0353
10	50	Biased	2.7415	2.7688	0.0273
11	30	Biased	2.6273	2.6412	0.0139
12	0	Correlation	2.6639	2.6638	-0.0001
13	0	Correlation	2.6982	2.6979	-0.0003
14	50	Unbiased	2.7288	2.7519	0.0231
15	20	Biased	2.7587	2.7557	-0.003
16	20	Unbiased	2.6323	2.6363	0.004
17	20	Biased	2.7441	2.7676	0.0235
18	20	Unbiased	2.7393	2.7538	0.0145
19	20	Biased	2.6721	2.6916	0.0195
20	50	Unbiased	2.7811	2.8003	0.0192
21	0	Correlation	2.6859	2.6869	0.001
22	50	Unbiased	2.6414	2.6851	0.0437
23	0	Correlation	2.6111	2.6118	0.0007
24	20	Biased	2.6484	2.652	0.0036
26	50	Biased	2.681	2.7196	0.0386
27	30	Unbiased	2.7748	2.7581	-0.0167
28	30	Biased	2.6823	2.673	-0.0093
29	30	Unbiased	2.6515	2.637	-0.0145
30	20	Biased	2.5971	2.619	0.0219
31	30	Unbiased	2.6629	2.6629	0
33	30	Biased	2.6568	2.6979	0.0411
34	50	Unbiased	2.769	2.7832	0.0142
35	20	Unbiased	2.7962	2.7838	-0.0124
41	30	Biased	2.6085	2.5843	-0.0242

Test Statistics (µA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.6111	2.6648	2.6982	0.038494	2.6118	2.6651	2.6979	0.038269	-0.0003	0.000325	0.001	0.00062383
20	2.5971	2.6855	2.7962	0.069441	2.619	2.6978	2.7838	0.062116	-0.0124	0.01231	0.0353	0.014171
30	2.6085	2.6554	2.7748	0.047285	2.5843	2.6597	2.7581	0.045329	-0.0242	0.00429	0.0411	0.020532
50	2.6196	2.7159	2.7811	0.053739	2.6149	2.7403	2.8021	0.058092	-0.0047	0.02442	0.064	0.019986

Device Test: 18.17 CURRENT|SS_0p3V/SS/4.5/4.5/0/1000/4.5/500kHz//@I_SS





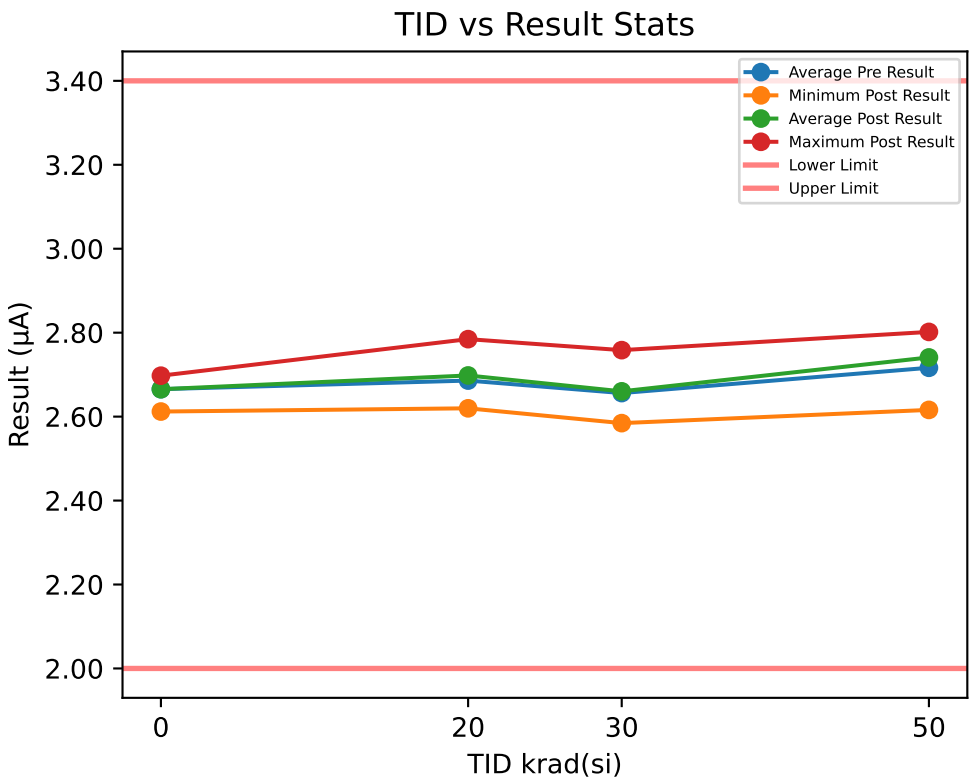
Test Results (Lower Limit = 2.0, Upper Limit = 3.4 (µA))

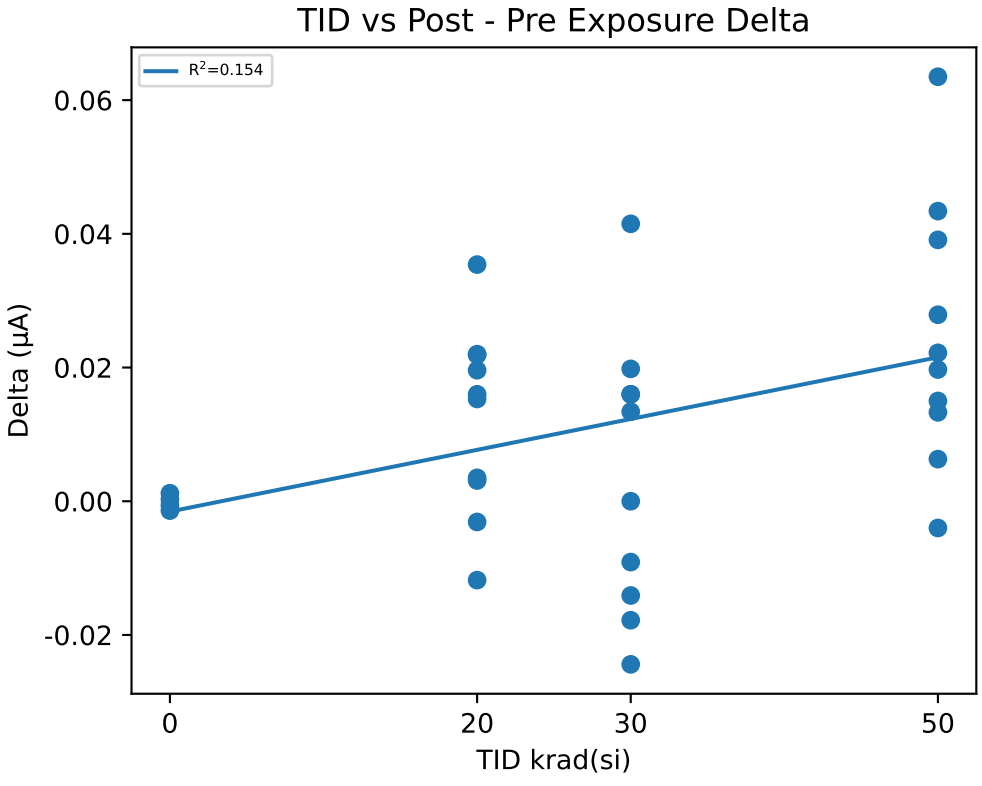
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	2.6954	2.7078	0.0124
2	20	Unbiased	2.654	2.6711	0.0171
3	50	Biased	2.6103	2.6066	-0.0037
4	30	Unbiased	2.6119	2.6281	0.0162
5	50	Unbiased	2.745	2.7515	0.0065
6	30	Biased	2.6234	2.6444	0.021
7	50	Biased	2.7286	2.7927	0.0641
8	30	Unbiased	2.628	2.6447	0.0167
9	20	Unbiased	2.5945	2.6298	0.0353
10	50	Biased	2.7322	2.7602	0.028
11	30	Biased	2.6181	2.6315	0.0134
12	0	Correlation	2.655	2.6544	-0.0006
13	0	Correlation	2.6889	2.6879	-0.001
14	50	Unbiased	2.7196	2.742	0.0224
15	20	Biased	2.7493	2.7469	-0.0024
16	20	Unbiased	2.6238	2.6271	0.0033
17	20	Biased	2.7338	2.7578	0.024
18	20	Unbiased	2.73	2.745	0.015
19	20	Biased	2.6633	2.6822	0.0189
20	50	Unbiased	2.771	2.7907	0.0197
21	0	Correlation	2.6773	2.6781	0.0008
22	50	Unbiased	2.6324	2.6768	0.0444
23	0	Correlation	2.6022	2.6027	0.0005
24	20	Biased	2.6384	2.6427	0.0043
26	50	Biased	2.6716	2.7105	0.0389
27	30	Unbiased	2.7649	2.7496	-0.0153
28	30	Biased	2.6729	2.6634	-0.0095
29	30	Unbiased	2.6425	2.6288	-0.0137
30	20	Biased	2.588	2.6103	0.0223
31	30	Unbiased	2.6539	2.6541	0.0002
33	30	Biased	2.6474	2.688	0.0406
34	50	Unbiased	2.7591	2.7742	0.0151
35	20	Unbiased	2.7867	2.7755	-0.0112
41	30	Biased	2.5991	2.5755	-0.0236

Test Statistics (µA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.6022	2.6559	2.6889	0.038434	2.6027	2.6558	2.6879	0.038076	-0.001	-7.5e-05	0.0008	0.00086168
20	2.588	2.6762	2.7867	0.069165	2.6103	2.6888	2.7755	0.062133	-0.0112	0.01266	0.0353	0.013952
30	2.5991	2.6462	2.7649	0.047037	2.5755	2.6508	2.7496	0.045258	-0.0236	0.0046	0.0406	0.020187
50	2.6103	2.7065	2.771	0.053558	2.6066	2.7313	2.7927	0.057737	-0.0037	0.02478	0.0641	0.019901

Device Test: 18.21 CURRENT|SS_0p3V/SS/5/5/0/1000/5/500kHz//@I_SS





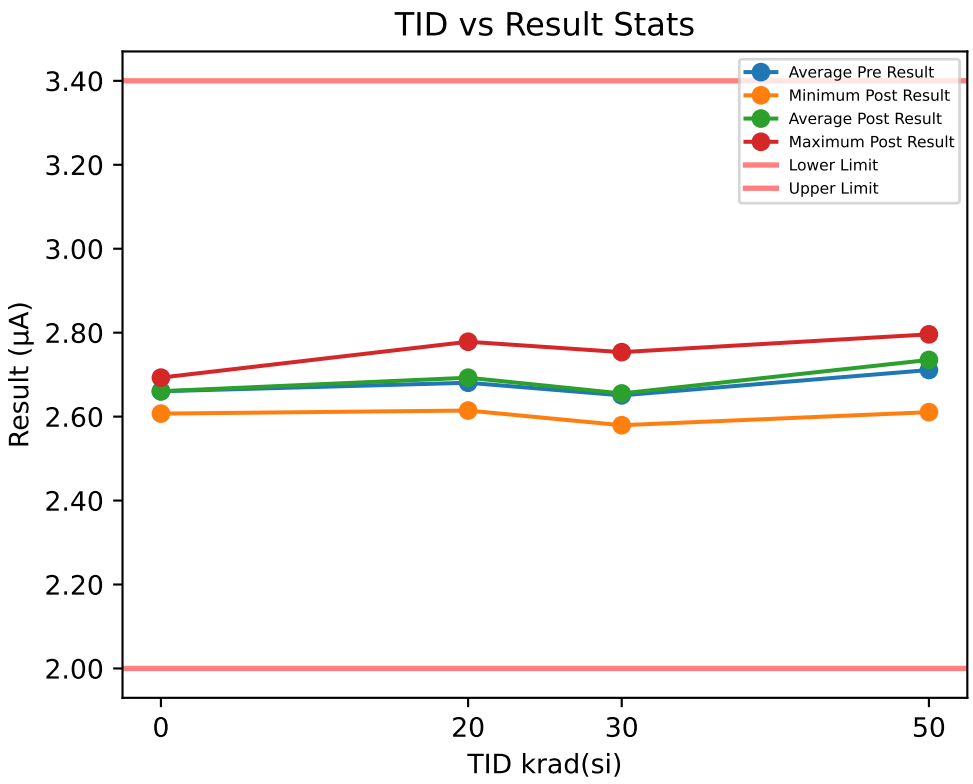
Test Results (Lower Limit = 2.0, Upper Limit = 3.4 (µA))

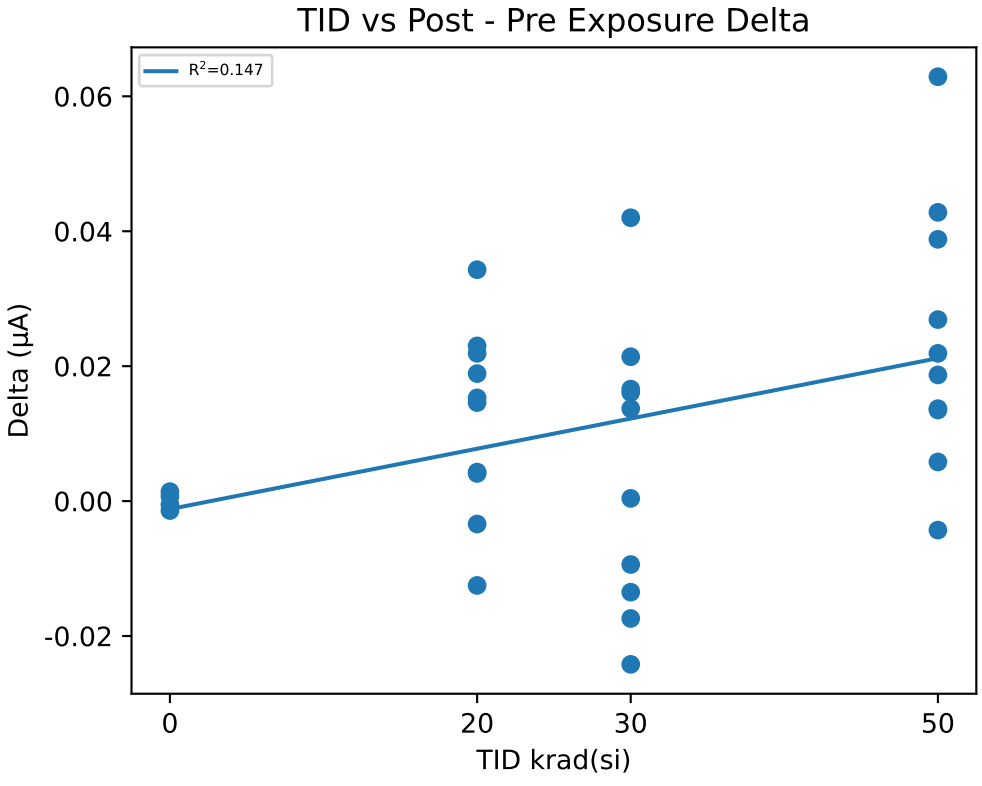
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	2.7047	2.718	0.0133
2	20	Unbiased	2.6638	2.6798	0.016
3	50	Biased	2.62	2.616	-0.004
4	30	Unbiased	2.6218	2.6378	0.016
5	50	Unbiased	2.7545	2.7608	0.0063
6	30	Biased	2.6333	2.6531	0.0198
7	50	Biased	2.7383	2.8018	0.0635
8	30	Unbiased	2.638	2.654	0.016
9	20	Unbiased	2.6039	2.6393	0.0354
10	50	Biased	2.7425	2.7704	0.0279
11	30	Biased	2.6276	2.641	0.0134
12	0	Correlation	2.6648	2.6642	-0.0006
13	0	Correlation	2.6989	2.6975	-0.0014
14	50	Unbiased	2.7296	2.7518	0.0222
15	20	Biased	2.7589	2.7558	-0.0031
16	20	Unbiased	2.6326	2.6361	0.0035
17	20	Biased	2.7447	2.7666	0.0219
18	20	Unbiased	2.7395	2.7548	0.0153
19	20	Biased	2.6726	2.6922	0.0196
20	50	Unbiased	2.7814	2.8011	0.0197
21	0	Correlation	2.6862	2.6874	0.0012
22	50	Unbiased	2.6419	2.6853	0.0434
23	0	Correlation	2.6118	2.6121	0.0003
24	20	Biased	2.6485	2.6516	0.0031
26	50	Biased	2.6816	2.7207	0.0391
27	30	Unbiased	2.7762	2.7584	-0.0178
28	30	Biased	2.6828	2.6737	-0.0091
29	30	Unbiased	2.6519	2.6378	-0.0141
30	20	Biased	2.5978	2.6198	0.022
31	30	Unbiased	2.6636	2.6636	0
33	30	Biased	2.6571	2.6986	0.0415
34	50	Unbiased	2.7691	2.7841	0.015
35	20	Unbiased	2.7964	2.7846	-0.0118
41	30	Biased	2.6089	2.5845	-0.0244

Test Statistics (µA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.6118	2.6654	2.6989	0.03842	2.6121	2.6653	2.6975	0.038108	-0.0014	-0.000125	0.0012	0.0011236
20	2.5978	2.6859	2.7964	0.06933	2.6198	2.6981	2.7846	0.062078	-0.0118	0.01219	0.0354	0.014047
30	2.6089	2.6561	2.7762	0.047464	2.5845	2.6603	2.7584	0.045342	-0.0244	0.00413	0.0415	0.020627
50	2.62	2.7164	2.7814	0.053728	2.616	2.741	2.8018	0.057935	-0.004	0.02464	0.0635	0.019693

Device Test: 18.25 CURRENT|SS_0p3V/SS/12/12/0/1000/5/500kHz//@I_SS





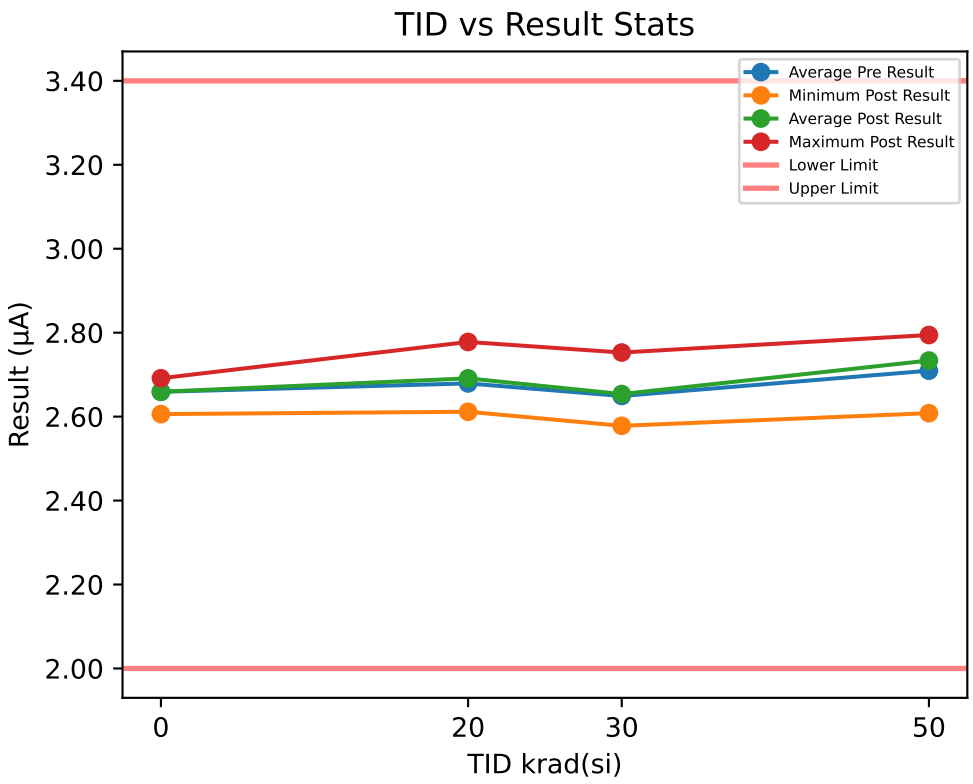
Test Results (Lower Limit = 2.0, Upper Limit = 3.4 (µA))

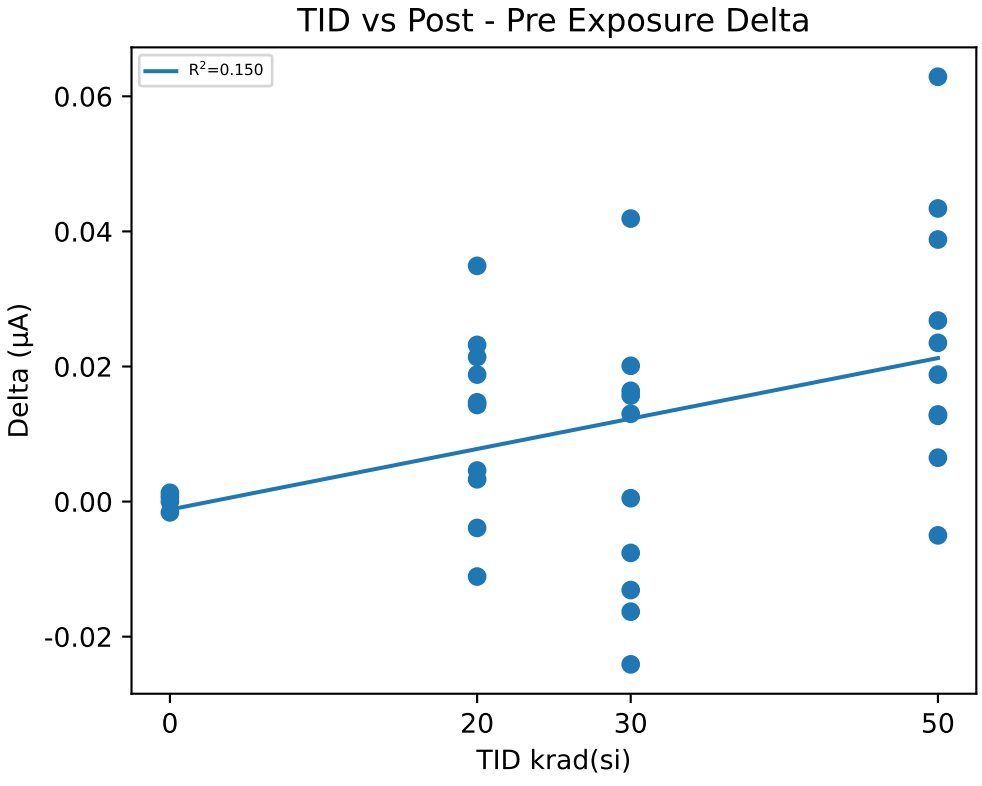
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	2.6987	2.7124	0.0137
2	20	Unbiased	2.6585	2.6738	0.0153
3	50	Biased	2.6149	2.6106	-0.0043
4	30	Unbiased	2.6155	2.6316	0.0161
5	50	Unbiased	2.7494	2.7552	0.0058
6	30	Biased	2.6279	2.6493	0.0214
7	50	Biased	2.7331	2.796	0.0629
8	30	Unbiased	2.6322	2.6488	0.0166
9	20	Unbiased	2.5981	2.6324	0.0343
10	50	Biased	2.7369	2.7638	0.0269
11	30	Biased	2.6221	2.6358	0.0137
12	0	Correlation	2.6598	2.6593	-0.0005
13	0	Correlation	2.6943	2.6929	-0.0014
14	50	Unbiased	2.7243	2.7462	0.0219
15	20	Biased	2.7541	2.7507	-0.0034
16	20	Unbiased	2.6275	2.6318	0.0043
17	20	Biased	2.7389	2.7619	0.023
18	20	Unbiased	2.7351	2.7497	0.0146
19	20	Biased	2.6672	2.6861	0.0189
20	50	Unbiased	2.776	2.7947	0.0187
21	0	Correlation	2.6811	2.6825	0.0014
22	50	Unbiased	2.637	2.6798	0.0428
23	0	Correlation	2.6065	2.6072	0.0007
24	20	Biased	2.6439	2.648	0.0041
26	50	Biased	2.6763	2.7151	0.0388
27	30	Unbiased	2.771	2.7536	-0.0174
28	30	Biased	2.6776	2.6682	-0.0094
29	30	Unbiased	2.6462	2.6327	-0.0135
30	20	Biased	2.5926	2.6145	0.0219
31	30	Unbiased	2.6578	2.6582	0.0004
33	30	Biased	2.6523	2.6943	0.042
34	50	Unbiased	2.7636	2.7771	0.0135
35	20	Unbiased	2.7909	2.7784	-0.0125
41	30	Biased	2.6037	2.5795	-0.0242

Test Statistics (µA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.6065	2.6604	2.6943	0.038658	2.6072	2.6605	2.6929	0.038193	-0.0014	5e-05	0.0014	0.001245
20	2.5926	2.6807	2.7909	0.06938	2.6145	2.6927	2.7784	0.062008	-0.0125	0.01205	0.0343	0.013907
30	2.6037	2.6506	2.771	0.047606	2.5795	2.6552	2.7536	0.045504	-0.0242	0.00457	0.042	0.020803
50	2.6149	2.711	2.776	0.053613	2.6106	2.7351	2.796	0.05759	-0.0043	0.02407	0.0629	0.01965

Device Test: 18.29 CURRENT|SS_0p3V/SS/14/14/0/1000/5/500kHz//@I_SS





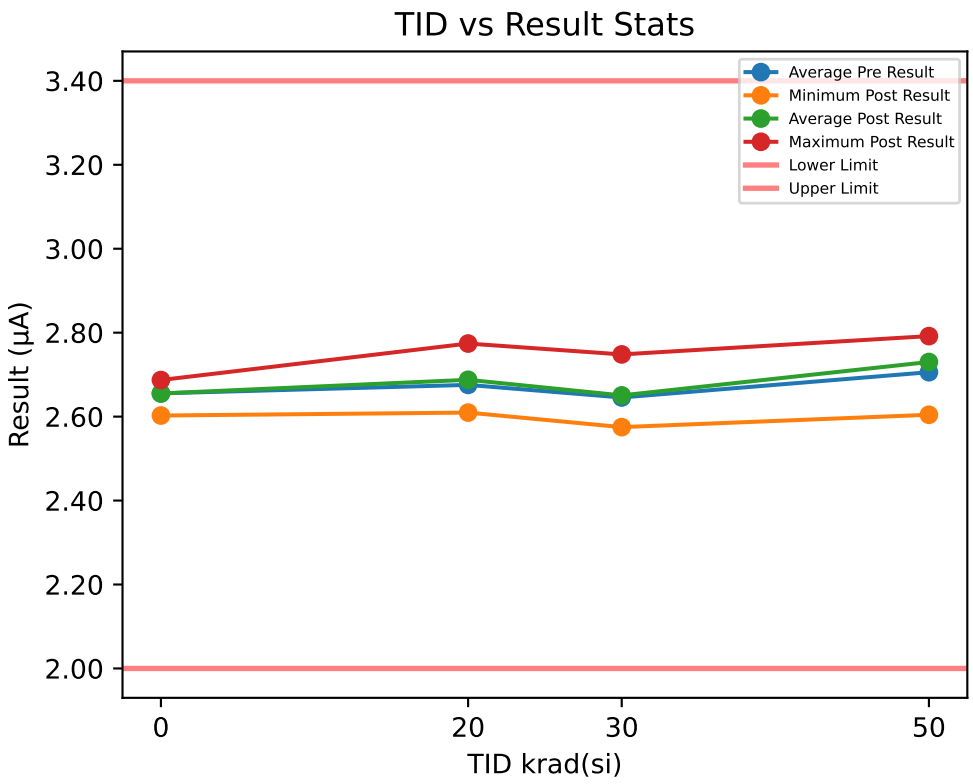
Test Results (Lower Limit = 2.0, Upper Limit = 3.4 (µA))

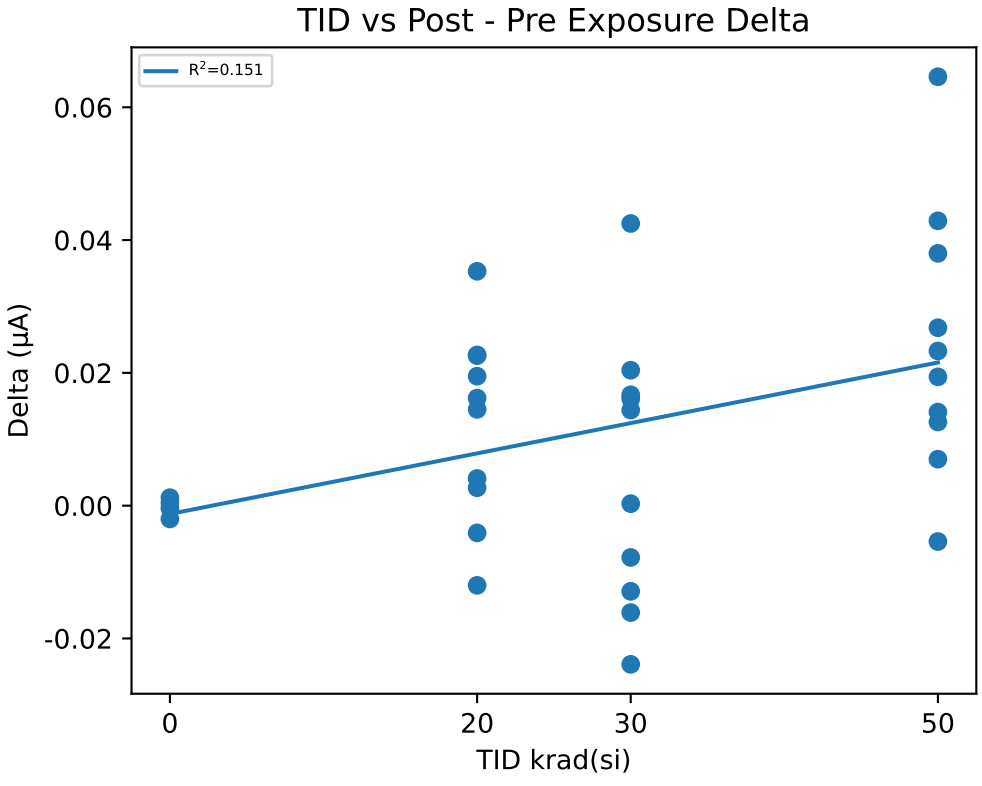
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	2.6971	2.71	0.0129
2	20	Unbiased	2.6571	2.6718	0.0147
3	50	Biased	2.6132	2.6082	-0.005
4	30	Unbiased	2.6141	2.6298	0.0157
5	50	Unbiased	2.7469	2.7534	0.0065
6	30	Biased	2.6264	2.6465	0.0201
7	50	Biased	2.7315	2.7944	0.0629
8	30	Unbiased	2.6307	2.6471	0.0164
9	20	Unbiased	2.5967	2.6316	0.0349
10	50	Biased	2.7351	2.7619	0.0268
11	30	Biased	2.6213	2.6343	0.013
12	0	Correlation	2.6586	2.6586	0
13	0	Correlation	2.693	2.6914	-0.0016
14	50	Unbiased	2.7228	2.7463	0.0235
15	20	Biased	2.7529	2.749	-0.0039
16	20	Unbiased	2.6263	2.6309	0.0046
17	20	Biased	2.7373	2.7605	0.0232
18	20	Unbiased	2.7336	2.7479	0.0143
19	20	Biased	2.6658	2.6846	0.0188
20	50	Unbiased	2.775	2.7938	0.0188
21	0	Correlation	2.6796	2.6809	0.0013
22	50	Unbiased	2.6355	2.6789	0.0434
23	0	Correlation	2.6053	2.606	0.0007
24	20	Biased	2.6422	2.6455	0.0033
26	50	Biased	2.6752	2.714	0.0388
27	30	Unbiased	2.769	2.7527	-0.0163
28	30	Biased	2.6758	2.6682	-0.0076
29	30	Unbiased	2.6447	2.6316	-0.0131
30	20	Biased	2.5902	2.6116	0.0214
31	30	Unbiased	2.6564	2.6569	0.0005
33	30	Biased	2.6508	2.6927	0.0419
34	50	Unbiased	2.7624	2.7751	0.0127
35	20	Unbiased	2.789	2.7779	-0.0111
41	30	Biased	2.6022	2.5781	-0.0241

Test Statistics (µA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.6053	2.6591	2.693	0.038575	2.606	2.6592	2.6914	0.038028	-0.0016	0.0001	0.0013	0.0012517
20	2.5902	2.6791	2.789	0.06943	2.6116	2.6911	2.7779	0.062279	-0.0111	0.01202	0.0349	0.0138
30	2.6022	2.6491	2.769	0.047394	2.5781	2.6538	2.7527	0.045691	-0.0241	0.00465	0.0419	0.020287
50	2.6132	2.7095	2.775	0.053628	2.6082	2.7336	2.7944	0.057788	-0.005	0.02413	0.0629	0.019837

Device Test: 18.33 CURRENT|SS_0p3V/SS/4.5/4.5/0/1000/4.5/1MHz//@I_SS





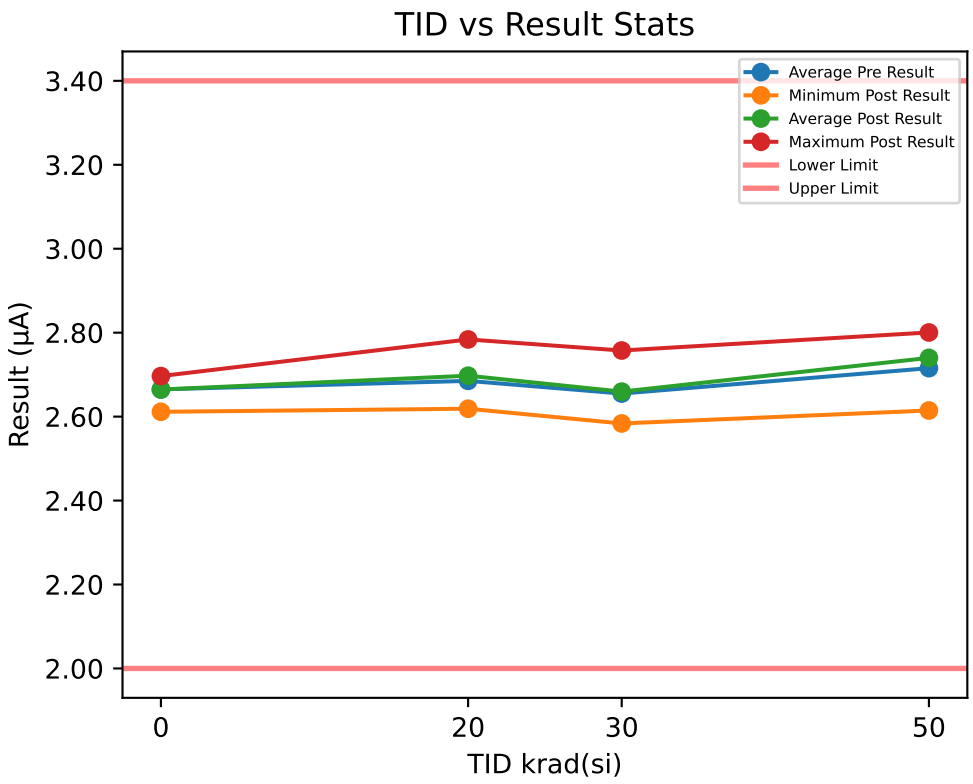
Test Results (Lower Limit = 2.0, Upper Limit = 3.4 (µA))

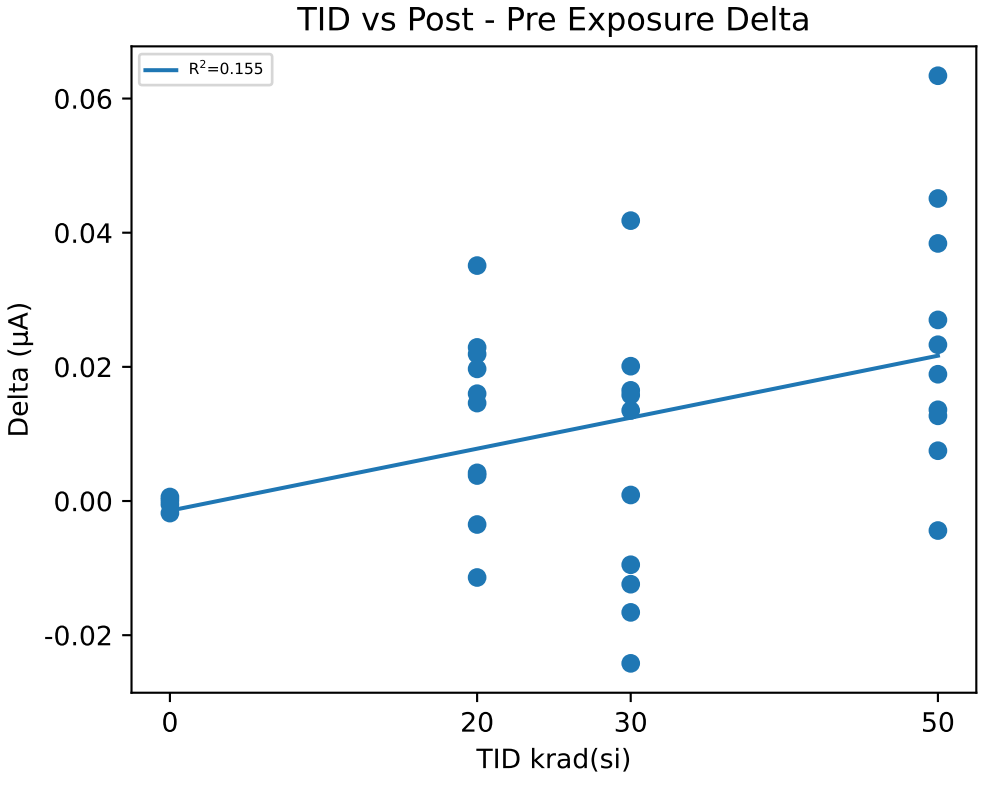
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	2.6946	2.7072	0.0126
2	20	Unbiased	2.6541	2.6703	0.0162
3	50	Biased	2.6098	2.6044	-0.0054
4	30	Unbiased	2.6112	2.6279	0.0167
5	50	Unbiased	2.7439	2.7509	0.007
6	30	Biased	2.6227	2.6431	0.0204
7	50	Biased	2.7272	2.7918	0.0646
8	30	Unbiased	2.6274	2.6435	0.0161
9	20	Unbiased	2.5934	2.6287	0.0353
10	50	Biased	2.7315	2.7583	0.0268
11	30	Biased	2.6178	2.6322	0.0144
12	0	Correlation	2.6546	2.6542	-0.0004
13	0	Correlation	2.6892	2.6872	-0.002
14	50	Unbiased	2.7189	2.7422	0.0233
15	20	Biased	2.749	2.7449	-0.0041
16	20	Unbiased	2.6233	2.6274	0.0041
17	20	Biased	2.7333	2.756	0.0227
18	20	Unbiased	2.7291	2.7436	0.0145
19	20	Biased	2.6625	2.682	0.0195
20	50	Unbiased	2.7706	2.79	0.0194
21	0	Correlation	2.6764	2.6768	0.0004
22	50	Unbiased	2.632	2.6749	0.0429
23	0	Correlation	2.6014	2.6026	0.0012
24	20	Biased	2.6379	2.6406	0.0027
26	50	Biased	2.6711	2.7091	0.038
27	30	Unbiased	2.7643	2.7482	-0.0161
28	30	Biased	2.672	2.6642	-0.0078
29	30	Unbiased	2.642	2.6291	-0.0129
30	20	Biased	2.587	2.6096	0.0226
31	30	Unbiased	2.6534	2.6537	0.0003
33	30	Biased	2.6465	2.689	0.0425
34	50	Unbiased	2.7584	2.7725	0.0141
35	20	Unbiased	2.7861	2.7741	-0.012
41	30	Biased	2.5989	2.575	-0.0239

Test Statistics (µA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.6014	2.6554	2.6892	0.03873	2.6026	2.6552	2.6872	0.037675	-0.002	-0.0002	0.0012	0.0013663
20	2.587	2.6756	2.7861	0.069271	2.6096	2.6877	2.7741	0.061731	-0.012	0.01215	0.0353	0.014274
30	2.5989	2.6456	2.7643	0.046968	2.575	2.6506	2.7482	0.045133	-0.0239	0.00497	0.0425	0.02049
50	2.6098	2.7058	2.7706	0.053437	2.6044	2.7301	2.7918	0.058099	-0.0054	0.02433	0.0646	0.020031

Device Test: 18.37 CURRENT|SS_0p3V/SS/5/5/0/1000/5/1MHz//@I_SS





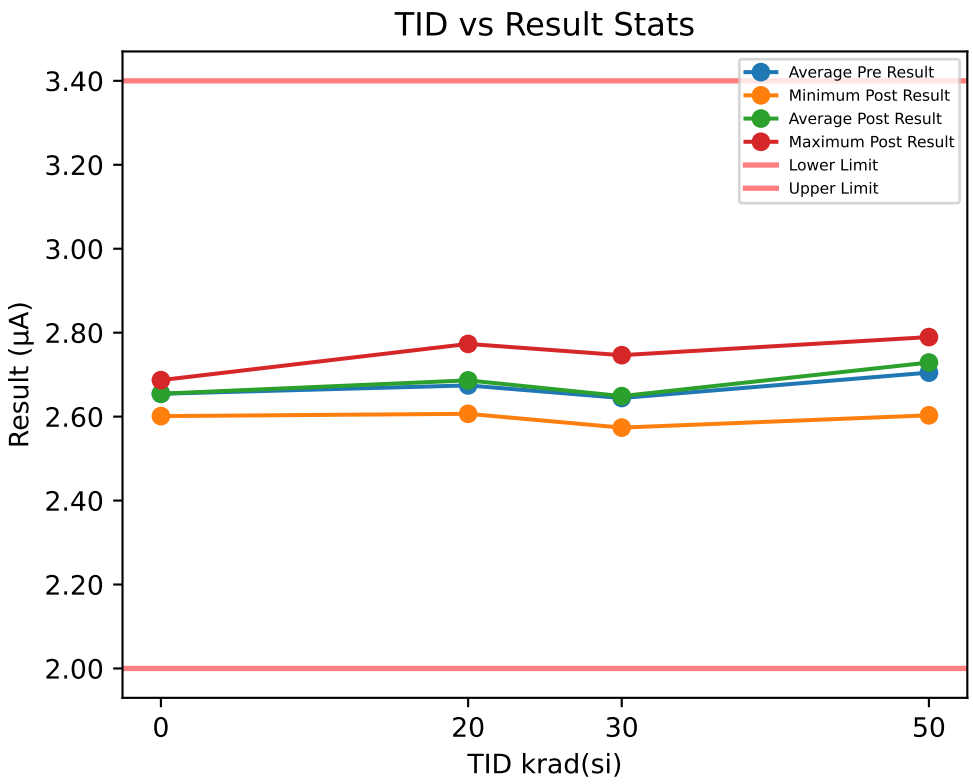
Test Results (Lower Limit = 2.0, Upper Limit = 3.4 (µA))

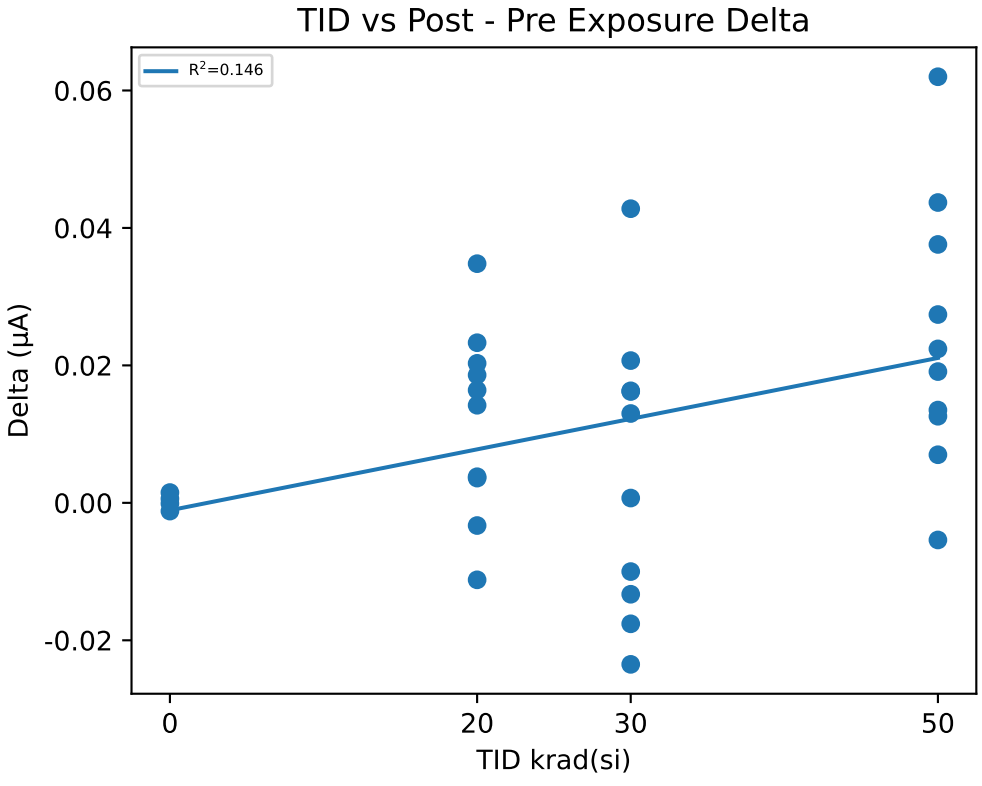
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	2.7039	2.7166	0.0127
2	20	Unbiased	2.6631	2.6791	0.016
3	50	Biased	2.619	2.6146	-0.0044
4	30	Unbiased	2.6205	2.637	0.0165
5	50	Unbiased	2.7534	2.7609	0.0075
6	30	Biased	2.6321	2.6522	0.0201
7	50	Biased	2.7371	2.8005	0.0634
8	30	Unbiased	2.6371	2.6529	0.0158
9	20	Unbiased	2.6032	2.6383	0.0351
10	50	Biased	2.742	2.769	0.027
11	30	Biased	2.6271	2.6406	0.0135
12	0	Correlation	2.664	2.6635	-0.0005
13	0	Correlation	2.6984	2.6966	-0.0018
14	50	Unbiased	2.7286	2.7519	0.0233
15	20	Biased	2.7581	2.7546	-0.0035
16	20	Unbiased	2.6321	2.6359	0.0038
17	20	Biased	2.7438	2.7667	0.0229
18	20	Unbiased	2.7393	2.7539	0.0146
19	20	Biased	2.672	2.6917	0.0197
20	50	Unbiased	2.7801	2.799	0.0189
21	0	Correlation	2.6864	2.6865	0.0001
22	50	Unbiased	2.6408	2.6859	0.0451
23	0	Correlation	2.6109	2.6115	0.0006
24	20	Biased	2.6477	2.6519	0.0042
26	50	Biased	2.6811	2.7195	0.0384
27	30	Unbiased	2.7741	2.7575	-0.0166
28	30	Biased	2.6815	2.672	-0.0095
29	30	Unbiased	2.6509	2.6385	-0.0124
30	20	Biased	2.5969	2.6188	0.0219
31	30	Unbiased	2.6623	2.6632	0.0009
33	30	Biased	2.656	2.6978	0.0418
34	50	Unbiased	2.7683	2.7819	0.0136
35	20	Unbiased	2.7953	2.7839	-0.0114
41	30	Biased	2.6079	2.5837	-0.0242

Test Statistics (µA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.6109	2.6649	2.6984	0.038735	2.6115	2.6645	2.6966	0.037967	-0.0018	-0.0004	0.0006	0.001036
20	2.5969	2.6852	2.7953	0.069287	2.6188	2.6975	2.7839	0.062039	-0.0114	0.01233	0.0351	0.013933
30	2.6079	2.655	2.7741	0.047129	2.5837	2.6595	2.7575	0.0452	-0.0242	0.00459	0.0418	0.020414
50	2.619	2.7154	2.7801	0.053695	2.6146	2.74	2.8005	0.057673	-0.0044	0.02455	0.0634	0.019866

Device Test: 18.41 CURRENT|SS_0p3V/SS/12/12/0/1000/5/1MHz//@I_SS





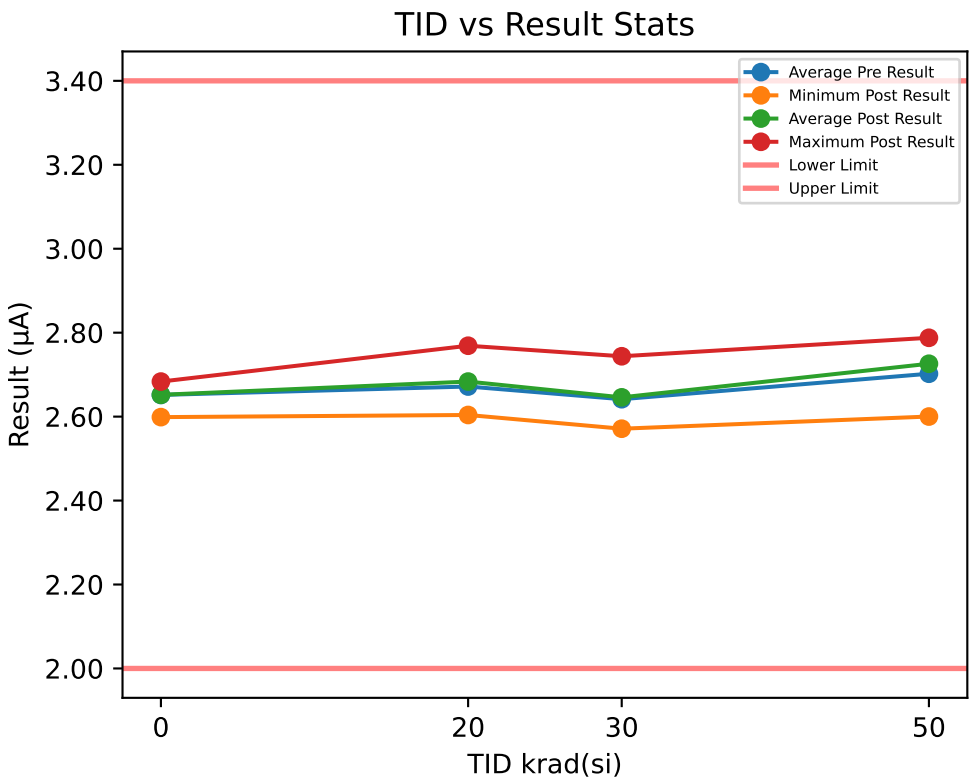
Test Results (Lower Limit = 2.0, Upper Limit = 3.4 (µA))

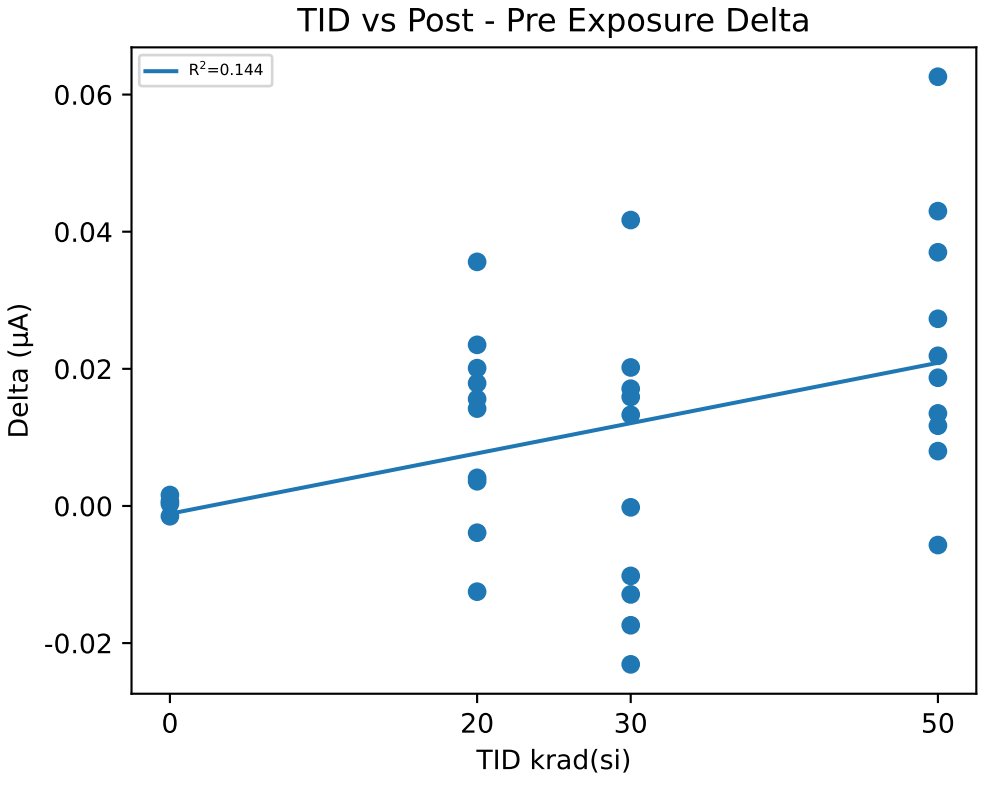
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	2.6919	2.7045	0.0126
2	20	Unbiased	2.6514	2.6678	0.0164
3	50	Biased	2.6085	2.6031	-0.0054
4	30	Unbiased	2.6087	2.625	0.0163
5	50	Unbiased	2.7422	2.7492	0.007
6	30	Biased	2.622	2.6427	0.0207
7	50	Biased	2.7275	2.7895	0.062
8	30	Unbiased	2.6259	2.6421	0.0162
9	20	Unbiased	2.5918	2.6266	0.0348
10	50	Biased	2.731	2.7584	0.0274
11	30	Biased	2.6166	2.6296	0.013
12	0	Correlation	2.6542	2.6541	-0.0001
13	0	Correlation	2.6881	2.6869	-0.0012
14	50	Unbiased	2.7185	2.7409	0.0224
15	20	Biased	2.7479	2.7446	-0.0033
16	20	Unbiased	2.6217	2.6253	0.0036
17	20	Biased	2.7325	2.7558	0.0233
18	20	Unbiased	2.7287	2.7429	0.0142
19	20	Biased	2.661	2.6796	0.0186
20	50	Unbiased	2.7701	2.7892	0.0191
21	0	Correlation	2.6747	2.6762	0.0015
22	50	Unbiased	2.6311	2.6748	0.0437
23	0	Correlation	2.6006	2.6012	0.0006
24	20	Biased	2.6375	2.6413	0.0038
26	50	Biased	2.6703	2.7079	0.0376
27	30	Unbiased	2.764	2.7464	-0.0176
28	30	Biased	2.6717	2.6617	-0.01
29	30	Unbiased	2.6395	2.6262	-0.0133
30	20	Biased	2.5864	2.6067	0.0203
31	30	Unbiased	2.6518	2.6525	0.0007
33	30	Biased	2.6457	2.6885	0.0428
34	50	Unbiased	2.7576	2.7711	0.0135
35	20	Unbiased	2.7844	2.7732	-0.0112
41	30	Biased	2.5973	2.5738	-0.0235

Test Statistics (µA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.6006	2.6544	2.6881	0.038481	2.6012	2.6546	2.6869	0.03813	-0.0012	0.0002	0.0015	0.0011402
20	2.5864	2.6743	2.7844	0.069315	2.6067	2.6864	2.7732	0.062377	-0.0112	0.01205	0.0348	0.013721
30	2.5973	2.6443	2.764	0.047422	2.5738	2.6488	2.7464	0.045258	-0.0235	0.00453	0.0428	0.020794
50	2.6085	2.7049	2.7701	0.053647	2.6031	2.7289	2.7895	0.058027	-0.0054	0.02399	0.062	0.019575

Device Test: 18.45 CURRENT|SS_0p3V/SS/14/14/0/1000/5/1MHz//@I_SS





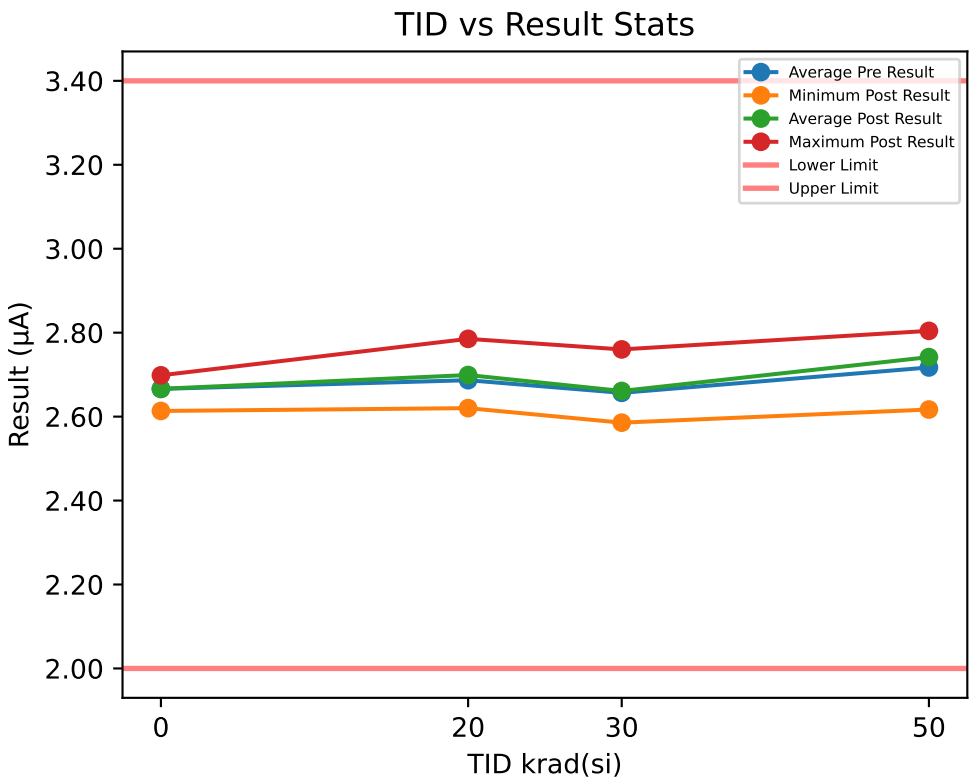
Test Results (Lower Limit = 2.0, Upper Limit = 3.4 (µA))

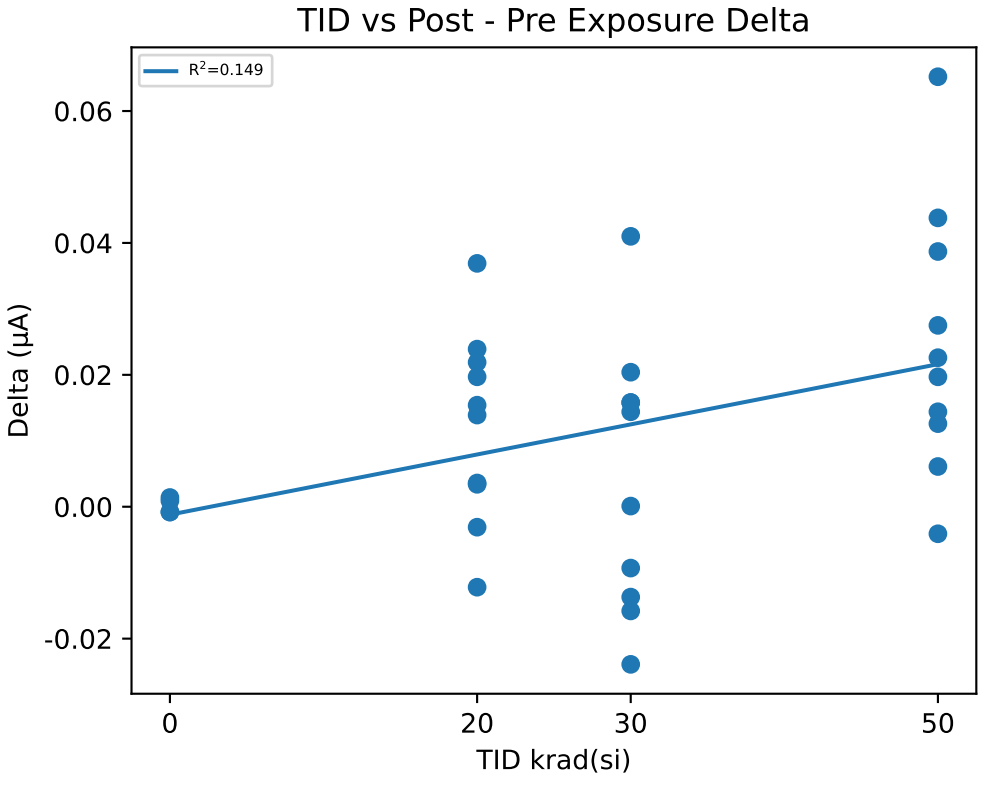
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	2.6888	2.7005	0.0117
2	20	Unbiased	2.6489	2.6645	0.0156
3	50	Biased	2.6059	2.6002	-0.0057
4	30	Unbiased	2.6052	2.6211	0.0159
5	50	Unbiased	2.7398	2.7478	0.008
6	30	Biased	2.6192	2.6394	0.0202
7	50	Biased	2.7252	2.7878	0.0626
8	30	Unbiased	2.6227	2.6398	0.0171
9	20	Unbiased	2.589	2.6246	0.0356
10	50	Biased	2.7285	2.7558	0.0273
11	30	Biased	2.6136	2.6269	0.0133
12	0	Correlation	2.6519	2.6522	0.0003
13	0	Correlation	2.685	2.6835	-0.0015
14	50	Unbiased	2.7156	2.7375	0.0219
15	20	Biased	2.7458	2.7419	-0.0039
16	20	Unbiased	2.619	2.6231	0.0041
17	20	Biased	2.7299	2.7534	0.0235
18	20	Unbiased	2.7262	2.7404	0.0142
19	20	Biased	2.6581	2.676	0.0179
20	50	Unbiased	2.7673	2.786	0.0187
21	0	Correlation	2.6717	2.6733	0.0016
22	50	Unbiased	2.6284	2.6714	0.043
23	0	Correlation	2.5981	2.5988	0.0007
24	20	Biased	2.6348	2.6384	0.0036
26	50	Biased	2.6679	2.7049	0.037
27	30	Unbiased	2.7612	2.7438	-0.0174
28	30	Biased	2.669	2.6588	-0.0102
29	30	Unbiased	2.6366	2.6237	-0.0129
30	20	Biased	2.5838	2.6039	0.0201
31	30	Unbiased	2.6495	2.6493	-0.0002
33	30	Biased	2.6435	2.6852	0.0417
34	50	Unbiased	2.7543	2.7678	0.0135
35	20	Unbiased	2.7814	2.7689	-0.0125
41	30	Biased	2.5943	2.5712	-0.0231

Test Statistics (µA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.5981	2.6517	2.685	0.038218	2.5988	2.652	2.6835	0.037755	-0.0015	0.000275	0.0016	0.0013022
20	2.5838	2.6717	2.7814	0.069356	2.6039	2.6835	2.7689	0.062122	-0.0125	0.01182	0.0356	0.014115
30	2.5943	2.6415	2.7612	0.047552	2.5712	2.6459	2.7438	0.045259	-0.0231	0.00444	0.0417	0.020491
50	2.6059	2.7022	2.7673	0.053585	2.6002	2.726	2.7878	0.058275	-0.0057	0.0238	0.0626	0.019615

Device Test: 18.5 CURRENT|SS_0p3V/SS/5/5/0/1000/5/100kHz//@I_SS





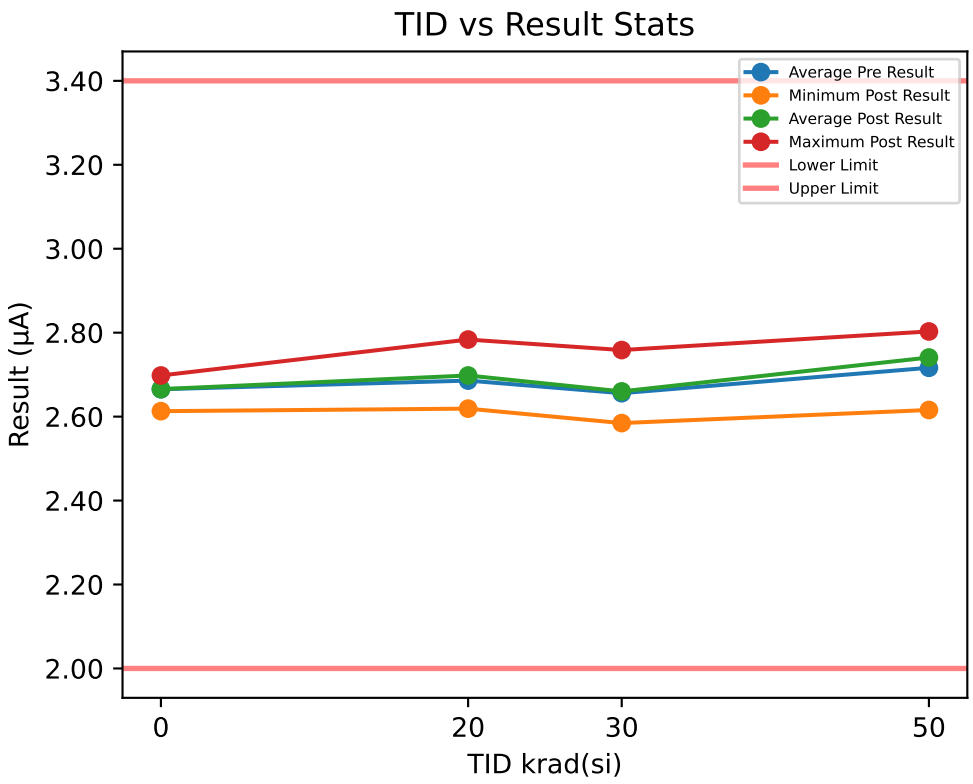
Test Results (Lower Limit = 2.0, Upper Limit = 3.4 (µA))

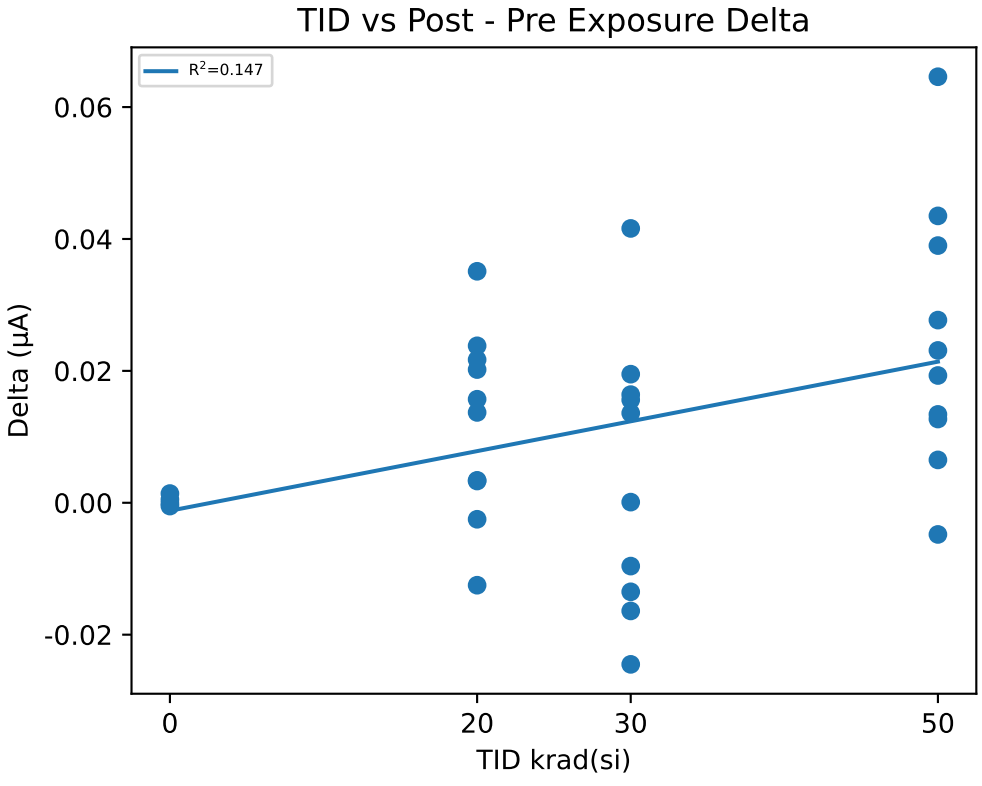
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	2.7055	2.7181	0.0126
2	20	Unbiased	2.6651	2.6805	0.0154
3	50	Biased	2.621	2.6169	-0.0041
4	30	Unbiased	2.6223	2.6381	0.0158
5	50	Unbiased	2.7553	2.7614	0.0061
6	30	Biased	2.6336	2.654	0.0204
7	50	Biased	2.7391	2.8043	0.0652
8	30	Unbiased	2.6389	2.6547	0.0158
9	20	Unbiased	2.6042	2.6411	0.0369
10	50	Biased	2.7434	2.7709	0.0275
11	30	Biased	2.6286	2.643	0.0144
12	0	Correlation	2.6656	2.6648	-0.0008
13	0	Correlation	2.6992	2.6984	-0.0008
14	50	Unbiased	2.7302	2.7528	0.0226
15	20	Biased	2.7597	2.7566	-0.0031
16	20	Unbiased	2.6339	2.6373	0.0034
17	20	Biased	2.745	2.7689	0.0239
18	20	Unbiased	2.7409	2.7548	0.0139
19	20	Biased	2.6735	2.6932	0.0197
20	50	Unbiased	2.7816	2.8013	0.0197
21	0	Correlation	2.6873	2.6882	0.0009
22	50	Unbiased	2.6428	2.6866	0.0438
23	0	Correlation	2.6121	2.6135	0.0014
24	20	Biased	2.6493	2.6529	0.0036
26	50	Biased	2.6824	2.7211	0.0387
27	30	Unbiased	2.7759	2.7601	-0.0158
28	30	Biased	2.683	2.6737	-0.0093
29	30	Unbiased	2.6527	2.639	-0.0137
30	20	Biased	2.5983	2.6202	0.0219
31	30	Unbiased	2.6642	2.6643	0.0001
33	30	Biased	2.6577	2.6987	0.041
34	50	Unbiased	2.7699	2.7843	0.0144
35	20	Unbiased	2.7975	2.7853	-0.0122
41	30	Biased	2.6095	2.5856	-0.0239

Test Statistics (µA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.6121	2.666	2.6992	0.038563	2.6135	2.6662	2.6984	0.03786	-0.0008	0.000175	0.0014	0.0011442
20	2.5983	2.6867	2.7975	0.069435	2.6202	2.6991	2.7853	0.062035	-0.0122	0.01234	0.0369	0.014496
30	2.6095	2.6566	2.7759	0.04717	2.5856	2.6611	2.7601	0.045363	-0.0239	0.00448	0.041	0.020271
50	2.621	2.7171	2.7816	0.053592	2.6169	2.7418	2.8043	0.057967	-0.0041	0.02465	0.0652	0.020183

Device Test: 18.9 CURRENT|SS_0p3V/SS/12/12/0/1000/5/100kHz//@I_SS





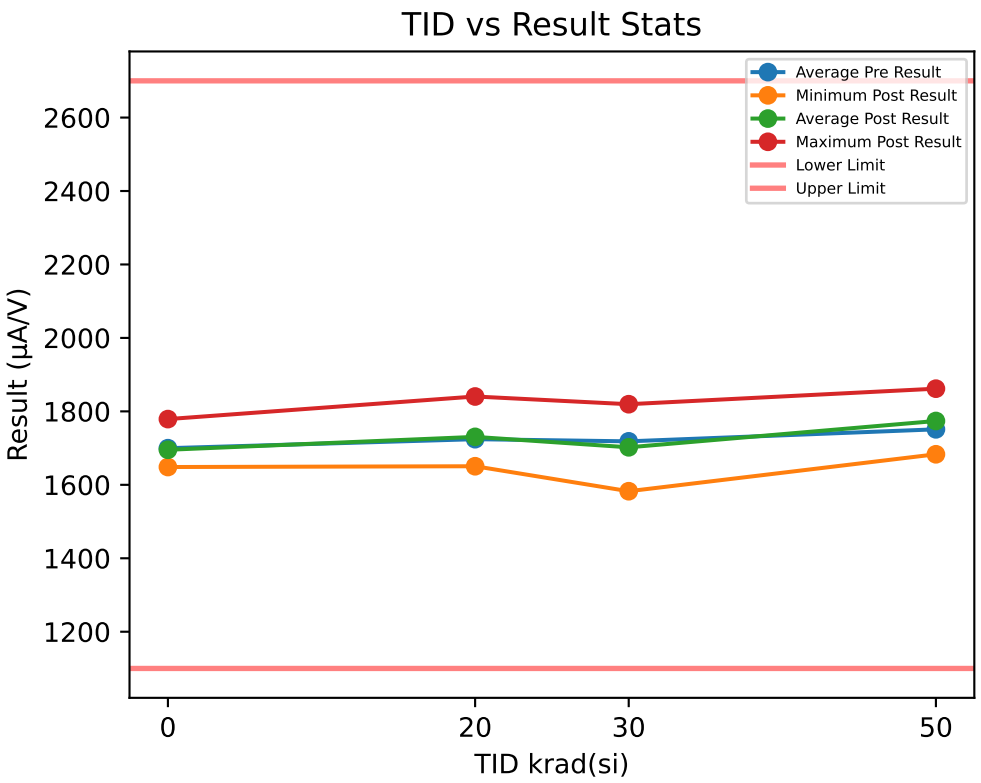
Test Results (Lower Limit = 2.0, Upper Limit = 3.4 (µA))

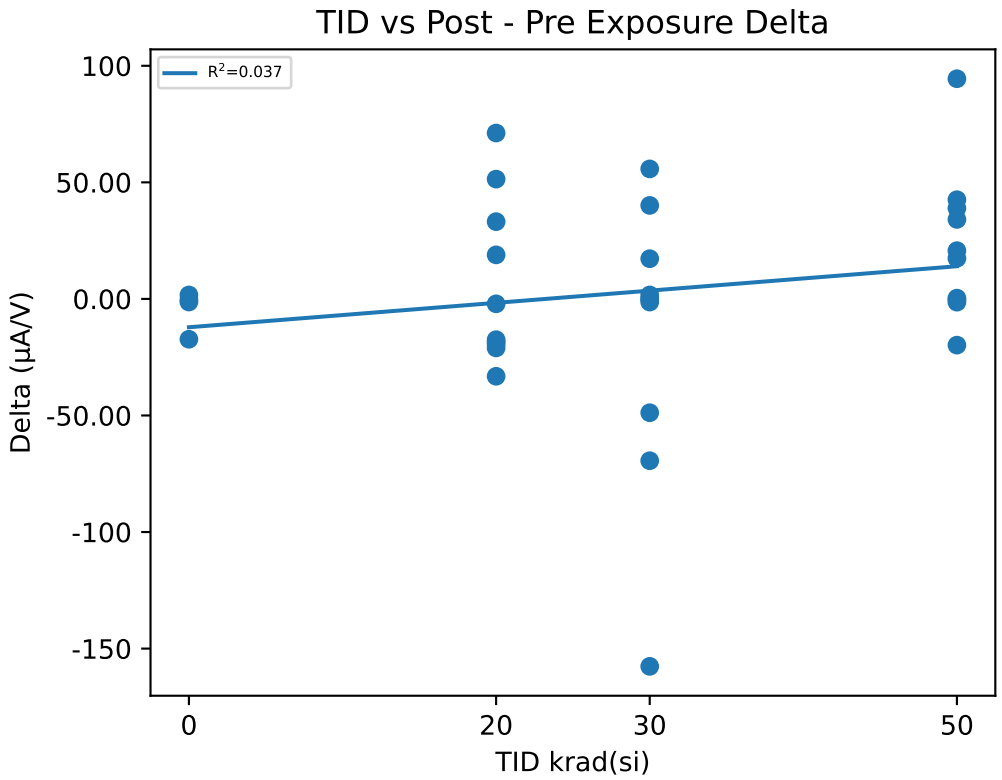
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	2.7047	2.7174	0.0127
2	20	Unbiased	2.6648	2.6805	0.0157
3	50	Biased	2.6206	2.6158	-0.0048
4	30	Unbiased	2.6214	2.637	0.0156
5	50	Unbiased	2.7545	2.761	0.0065
6	30	Biased	2.6326	2.6521	0.0195
7	50	Biased	2.7383	2.8029	0.0646
8	30	Unbiased	2.6377	2.6541	0.0164
9	20	Unbiased	2.6032	2.6383	0.0351
10	50	Biased	2.742	2.7697	0.0277
11	30	Biased	2.6279	2.6415	0.0136
12	0	Correlation	2.6643	2.6642	-0.0001
13	0	Correlation	2.6985	2.698	-0.0005
14	50	Unbiased	2.7291	2.7522	0.0231
15	20	Biased	2.7586	2.7561	-0.0025
16	20	Unbiased	2.6329	2.6363	0.0034
17	20	Biased	2.7442	2.768	0.0238
18	20	Unbiased	2.7402	2.7539	0.0137
19	20	Biased	2.6721	2.6923	0.0202
20	50	Unbiased	2.7815	2.8008	0.0193
21	0	Correlation	2.6865	2.687	0.0005
22	50	Unbiased	2.6419	2.6854	0.0435
23	0	Correlation	2.6116	2.613	0.0014
24	20	Biased	2.6488	2.6521	0.0033
26	50	Biased	2.6817	2.7207	0.039
27	30	Unbiased	2.775	2.7586	-0.0164
28	30	Biased	2.6824	2.6728	-0.0096
29	30	Unbiased	2.6517	2.6382	-0.0135
30	20	Biased	2.5973	2.619	0.0217
31	30	Unbiased	2.6634	2.6635	0.0001
33	30	Biased	2.6569	2.6985	0.0416
34	50	Unbiased	2.7691	2.7825	0.0134
35	20	Unbiased	2.7961	2.7836	-0.0125
41	30	Biased	2.6091	2.5846	-0.0245

Test Statistics (µA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.6116	2.6652	2.6985	0.038455	2.613	2.6656	2.698	0.037755	-0.0005	0.000325	0.0014	0.00082614
20	2.5973	2.6858	2.7961	0.069352	2.619	2.698	2.7836	0.062169	-0.0125	0.01219	0.0351	0.014184
30	2.6091	2.6558	2.775	0.047141	2.5846	2.6601	2.7586	0.045349	-0.0245	0.00428	0.0416	0.020463
50	2.6206	2.7163	2.7815	0.053574	2.6158	2.7408	2.8029	0.057941	-0.0048	0.0245	0.0646	0.020175

Device Test: 19.1 LEVEL|TRANSCONDUCTANCE//4.5/4.5/0/0/4.5/500kHz//@EA_GM





Test Results (Lower Limit = 1100.0, Upper Limit = 2700.0 (µA/V))

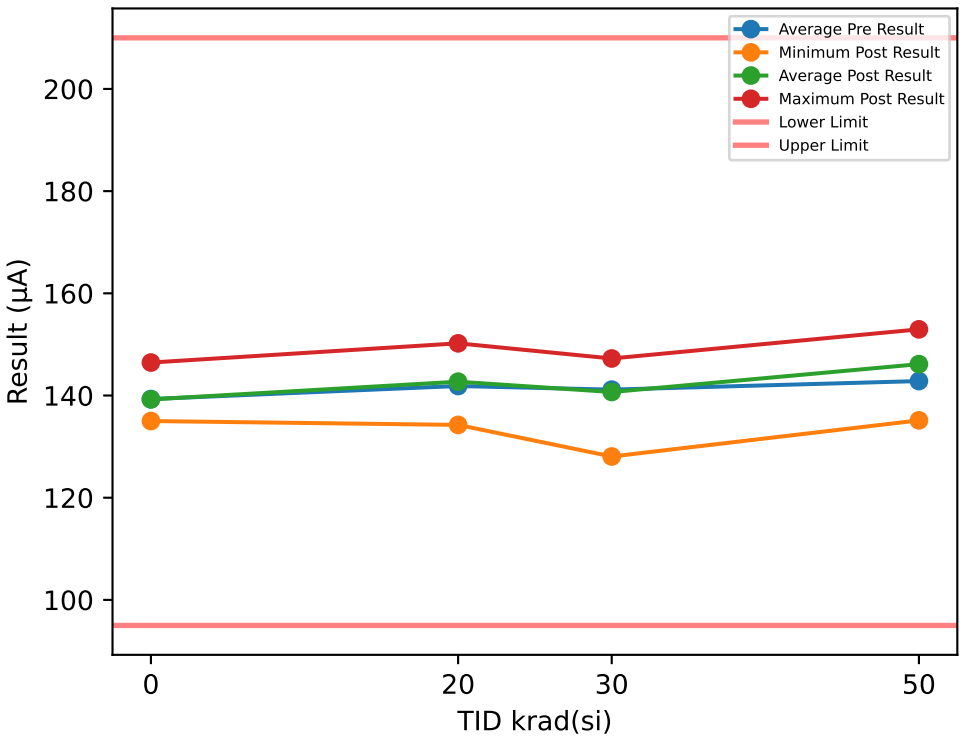
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	1720.8	1719.4	-1.3932
2	20	Unbiased	1759.3	1757.2	-2.1006
3	50	Biased	1649.1	1683.2	34.098
4	30	Unbiased	1779.4	1819.5	40.11
5	50	Unbiased	1684.5	1779	94.446
6	30	Biased	1667.6	1667.8	0.1575
7	50	Biased	1838.6	1859.3	20.702
8	30	Unbiased	1722	1721.8	-0.2209
9	20	Unbiased	1616.5	1667.9	51.391
10	50	Biased	1798.8	1779	-19.827
11	30	Biased	1720	1650.6	-69.405
12	0	Correlation	1779.4	1779	-0.4151
13	0	Correlation	1649.8	1648.5	-1.3374
14	50	Unbiased	1819.2	1861.8	42.557
15	20	Biased	1757.8	1740.3	-17.495
16	20	Unbiased	1617.6	1650.8	33.138
17	20	Biased	1778.1	1759.6	-18.509
18	20	Unbiased	1861.5	1840.5	-21.024
19	20	Biased	1757.8	1776.7	18.894
20	50	Unbiased	1779.4	1779.1	-0.3302
21	0	Correlation	1720.8	1703.5	-17.306
22	50	Unbiased	1740.1	1779.1	38.916
23	0	Correlation	1649.1	1650.8	1.6956
24	20	Biased	1759.8	1740.5	-19.352
26	50	Biased	1721.4	1721.8	0.3357
27	30	Unbiased	1757.8	1759.5	1.7052
28	30	Biased	1779.4	1796.6	17.254
29	30	Unbiased	1667	1665.6	-1.3571
30	20	Biased	1650.4	1721.6	71.157
31	30	Unbiased	1666.2	1617.4	-48.825
33	30	Biased	1684.5	1740.3	55.767
34	50	Unbiased	1759.3	1776.7	17.419
35	20	Unbiased	1683.8	1650.6	-33.189
41	30	Biased	1740.2	1582.6	-157.62

Test Statistics (µA/V)

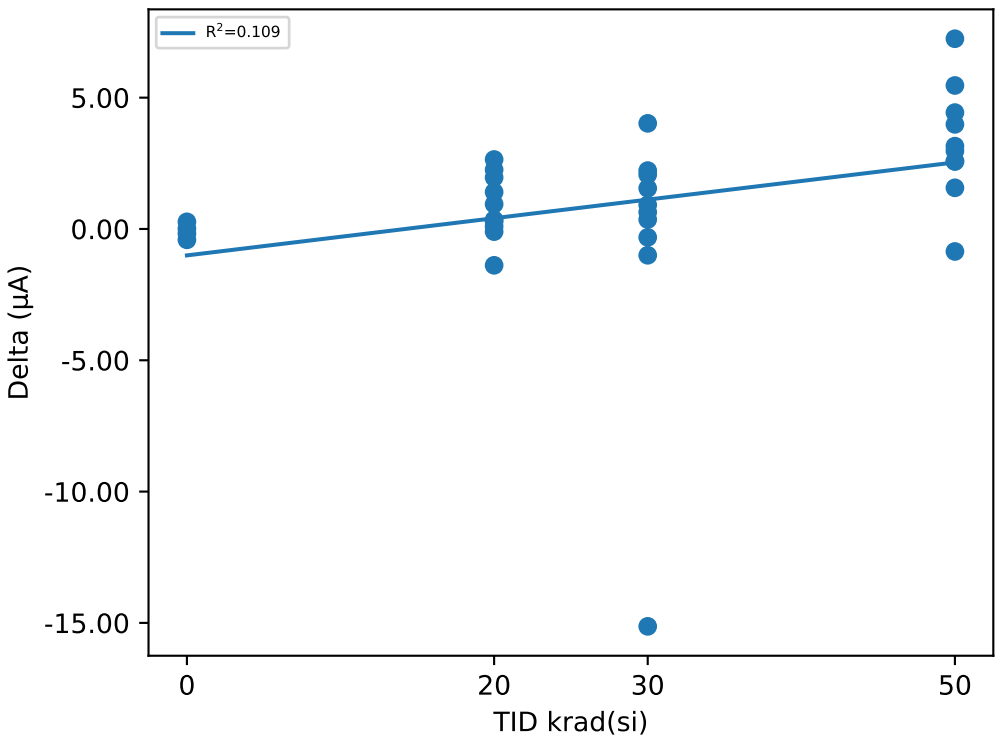
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1649.1	1699.8	1779.4	62.843	1648.5	1695.4	1779	61.225	-17.306	-4.3406	1.6956	8.736
20	1616.5	1724.3	1861.5	79.277	1650.6	1730.6	1840.5	60.311	-33.189	6.2909	71.157	35.488
30	1666.2	1718.4	1779.4	45.422	1582.6	1702.2	1819.5	77.802	-157.62	-16.243	55.767	61.849
50	1649.1	1751.1	1838.6	59.821	1683.2	1773.8	1861.8	56.822	-19.827	22.692	94.446	32.294

Device Test: 19.10 CURRENT|EA_SOURCE//12/12/0/0/5/500kHz//@EA_I_SOURCE

TID vs Result Stats



TID vs Post - Pre Exposure Delta



Test Results (Lower Limit = 95.0, Upper Limit = 210.0 (µA))

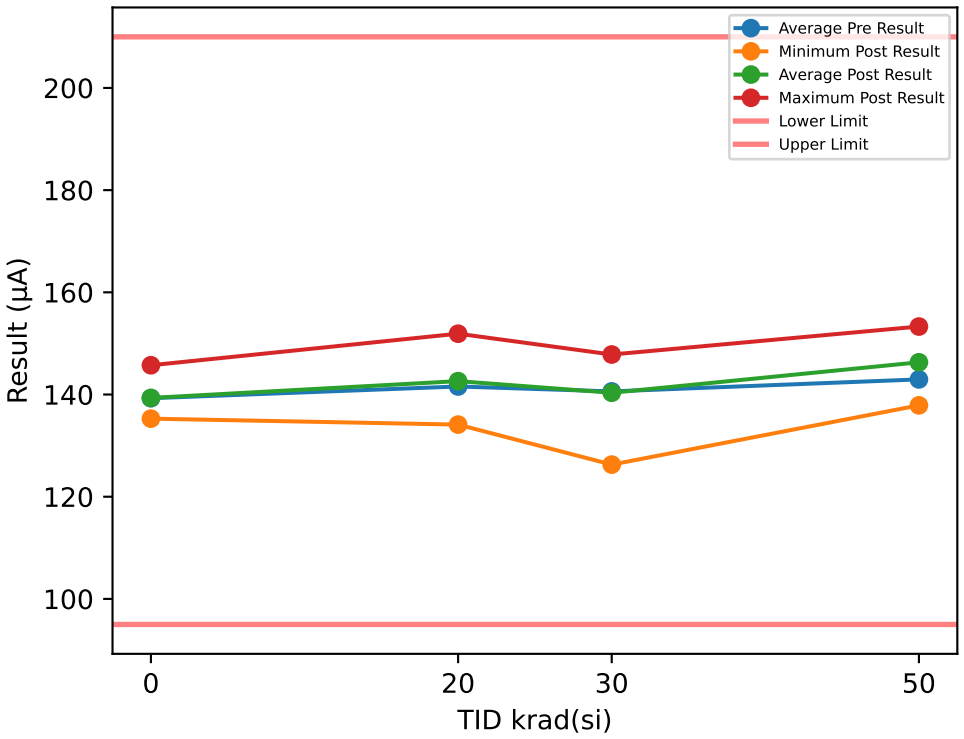
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	140.95	142.52	1.5665
2	20	Unbiased	146.35	146.7	0.3509
3	50	Biased	136	135.14	-0.8568
4	30	Unbiased	145.03	147.25	2.2229
5	50	Unbiased	142.02	146.45	4.4313
6	30	Biased	137.71	136.71	-1.0016
7	50	Biased	150.38	152.95	2.5713
8	30	Unbiased	143.49	144.4	0.9152
9	20	Unbiased	135.68	137.64	1.9591
10	50	Biased	145.78	148.94	3.1536
11	30	Biased	139.32	139.01	-0.3193
12	0	Correlation	146.63	146.45	-0.1738
13	0	Correlation	135.62	135.2	-0.4137
14	50	Unbiased	146.69	149.67	2.9728
15	20	Biased	144.32	142.93	-1.3842
16	20	Unbiased	133.31	134.25	0.9454
17	20	Biased	144.97	146.38	1.4056
18	20	Unbiased	149.93	150.21	0.2863
19	20	Biased	145.42	147.67	2.2558
20	50	Unbiased	142.39	146.37	3.9829
21	0	Correlation	140.01	140.28	0.2717
22	50	Unbiased	141.83	149.07	7.2434
23	0	Correlation	134.99	135	0.0141
24	20	Biased	142.26	142.36	0.098
26	50	Biased	139.44	144.9	5.4637
27	30	Unbiased	146.3	146.93	0.6374
28	30	Biased	145.37	146.92	1.5483
29	30	Unbiased	134.74	136.8	2.0679
30	20	Biased	139.97	142.62	2.6459
31	30	Unbiased	135.43	135.79	0.36
33	30	Biased	140.95	144.98	4.022
34	50	Unbiased	142.8	145.38	2.5799
35	20	Unbiased	136.4	136.3	-0.1014
41	30	Biased	143.2	128.06	-15.132

Test Statistics (µA)

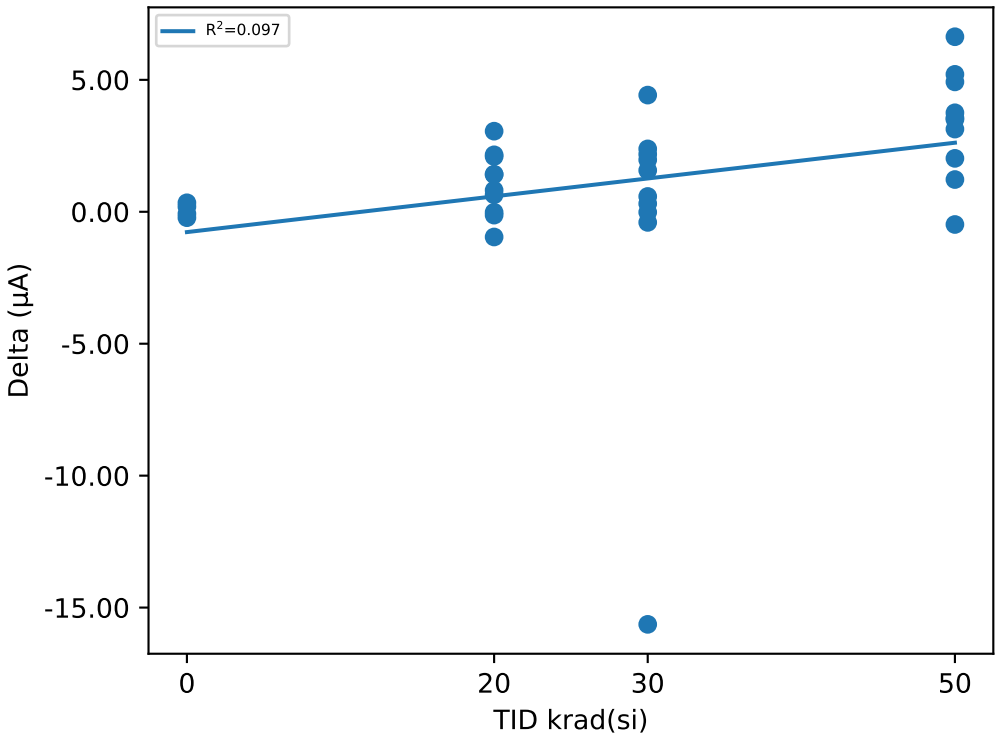
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	134.99	139.31	146.63	5.3649	135	139.24	146.45	5.3967	-0.4137	-0.075425	0.2717	0.29018
20	133.31	141.86	149.93	5.3595	134.25	142.71	150.21	5.2585	-1.3842	0.84614	2.6459	1.2373
30	134.74	141.15	146.3	4.19	128.06	140.69	147.25	6.4128	-15.132	-0.46789	4.022	5.3442
50	136	142.83	150.38	4.003	135.14	146.14	152.95	4.8489	-0.8568	3.3109	7.2434	2.1969

Device Test: 19.11 CURRENT|EA_SINK//12/12/0/0/5/500kHz//@EA_I_SINK

TID vs Result Stats



TID vs Post - Pre Exposure Delta



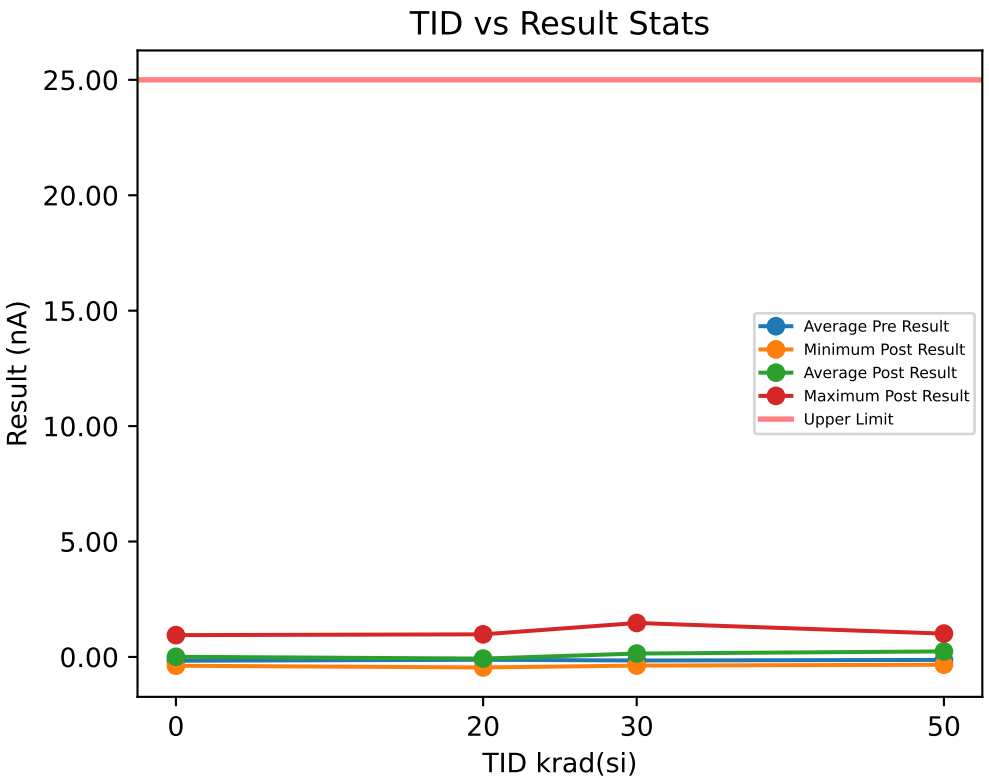
Test Results (Lower Limit = 95.0, Upper Limit = 210.0 (µA))

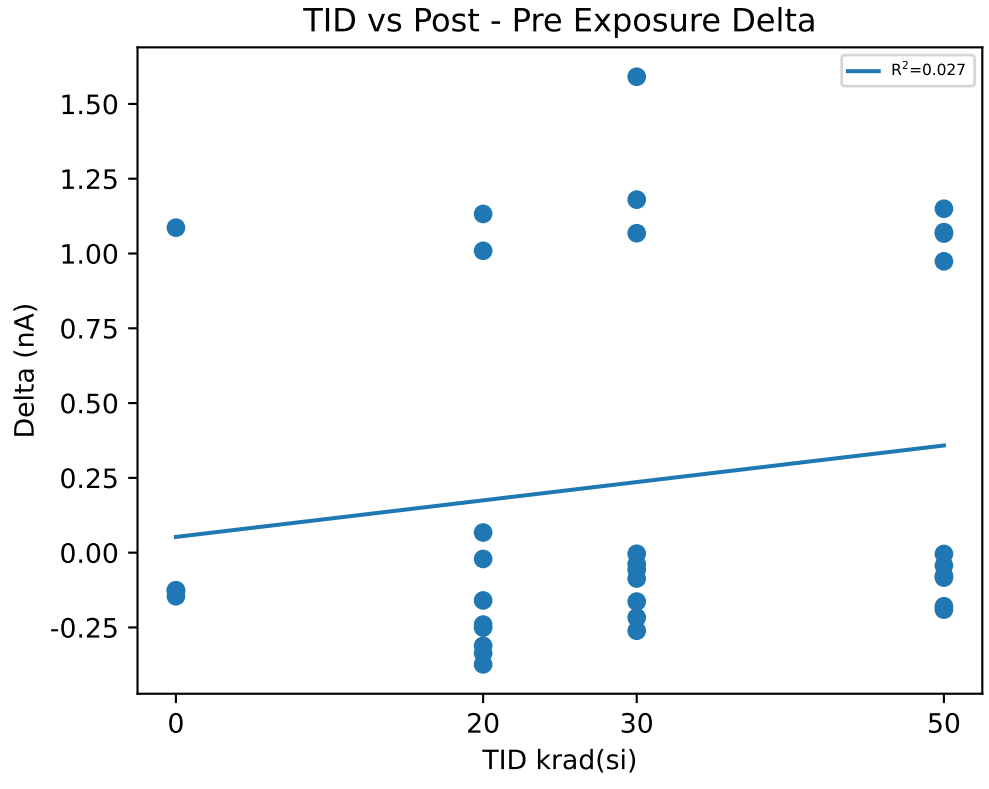
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	140.71	141.93	1.2224
2	20	Unbiased	146.47	147.12	0.644
3	50	Biased	138.36	137.88	-0.4814
4	30	Unbiased	145.65	147.83	2.1802
5	50	Unbiased	140.74	145.95	5.2089
6	30	Biased	138.84	138.44	-0.4019
7	50	Biased	150.17	153.3	3.1343
8	30	Unbiased	142.7	144.27	1.5706
9	20	Unbiased	135.02	137.12	2.0945
10	50	Biased	145.34	149.09	3.752
11	30	Biased	137.58	137.56	-0.0171
12	0	Correlation	145.81	145.73	-0.0764
13	0	Correlation	136.16	135.93	-0.2237
14	50	Unbiased	146.85	150.4	3.5569
15	20	Biased	144.67	143.72	-0.9548
16	20	Unbiased	133.3	134.12	0.8153
17	20	Biased	144.23	145.65	1.4217
18	20	Unbiased	150.49	151.9	1.4119
19	20	Biased	144.7	146.86	2.159
20	50	Unbiased	142.54	146.04	3.5007
21	0	Correlation	140.21	140.4	0.194
22	50	Unbiased	143.27	149.9	6.6341
23	0	Correlation	134.94	135.28	0.341
24	20	Biased	141.75	141.63	-0.1264
26	50	Biased	138.65	143.57	4.9227
27	30	Unbiased	146.34	146.92	0.5807
28	30	Biased	145.52	147.49	1.9686
29	30	Unbiased	134.11	136.5	2.3834
30	20	Biased	138.5	141.55	3.0549
31	30	Unbiased	133.71	134.02	0.3088
33	30	Biased	139.7	144.13	4.4226
34	50	Unbiased	142.95	144.98	2.0248
35	20	Unbiased	136.57	136.55	-0.0178
41	30	Biased	141.92	126.28	-15.636

Test Statistics (µA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	134.94	139.28	145.81	4.9013	135.28	139.34	145.73	4.8327	-0.2237	0.058725	0.341	0.2556
20	133.3	141.57	150.49	5.5359	134.12	142.62	151.9	5.5405	-0.9548	1.0502	3.0549	1.219
30	133.71	140.61	146.34	4.6108	126.28	140.34	147.83	7.0232	-15.636	-0.264	4.4226	5.5848
50	138.36	142.96	150.17	3.6928	137.88	146.31	153.3	4.5463	-0.4814	3.3475	6.6341	2.0535

Device Test: 19.12 CURRENT|EA//12/12/0/0/5/500kHz//@EA_IB





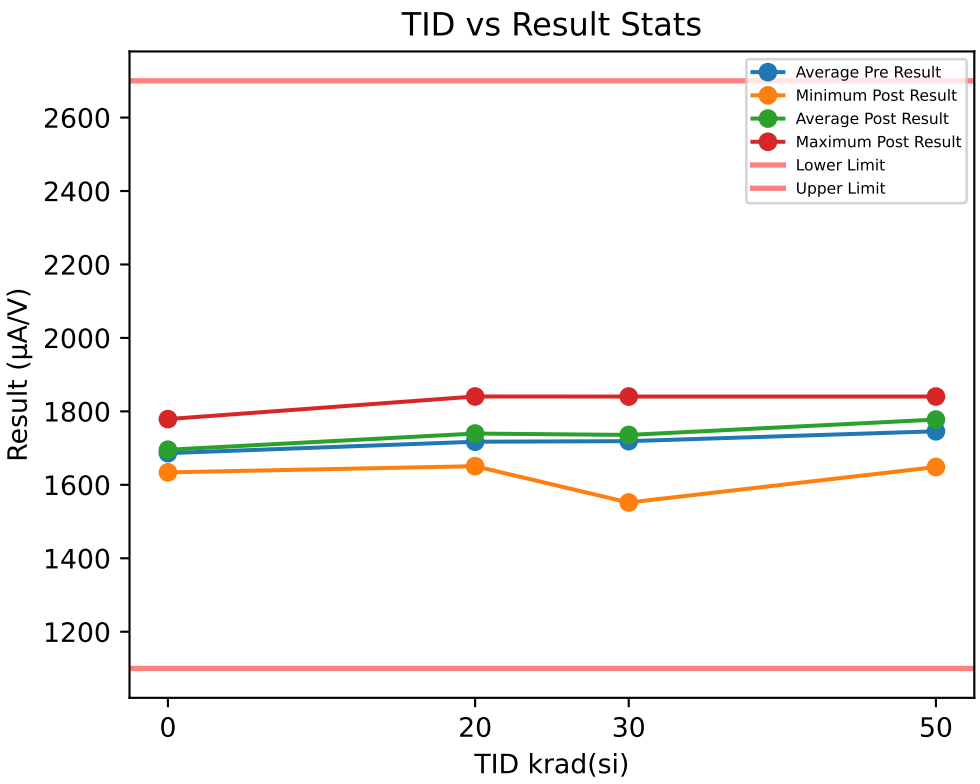
Test Results (Upper Limit = 25.0 (nA))

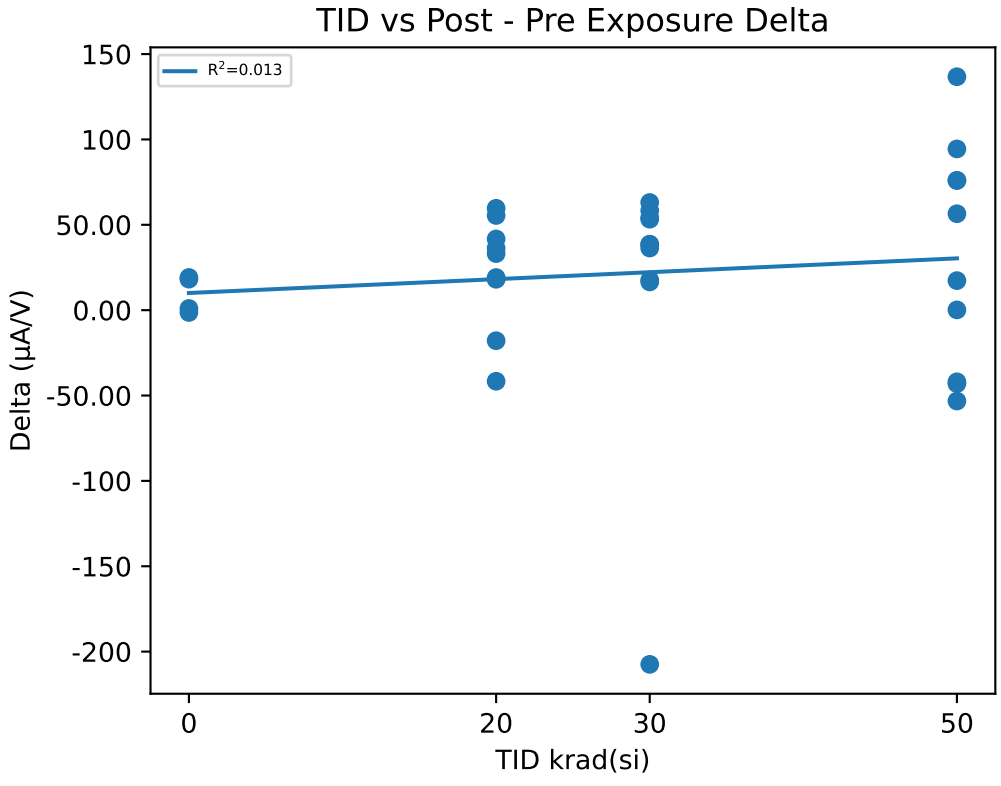
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	-0.0567	0.9172	0.9739
2	20	Unbiased	-0.1526	0.9797	1.1323
3	50	Biased	-0.0699	1.0016	1.0715
4	30	Unbiased	-0.1101	-0.2736	-0.1635
5	50	Unbiased	-0.2441	-0.2485	-0.0044
6	30	Biased	-0.19	-0.2765	-0.0865
7	50	Biased	-0.1386	1.011	1.1496
8	30	Unbiased	-0.1132	-0.3742	-0.261
9	20	Unbiased	-0.3097	-0.2424	0.0673
10	50	Biased	-0.2119	-0.2953	-0.0834
11	30	Biased	-0.1636	-0.1673	-0.0037
12	0	Correlation	-0.0508	-0.1767	-0.1259
13	0	Correlation	-0.141	0.9454	1.0864
14	50	Unbiased	-0.1182	-0.1956	-0.0774
15	20	Biased	-0.1667	-0.3265	-0.1598
16	20	Unbiased	-0.1194	-0.4553	-0.3359
17	20	Biased	-0.0098	-0.3212	-0.3114
18	20	Unbiased	-0.1276	-0.368	-0.2404
19	20	Biased	-0.0824	0.9266	1.009
20	50	Unbiased	-0.0476	-0.2268	-0.1792
21	0	Correlation	-0.2347	-0.3804	-0.1457
22	50	Unbiased	-0.1869	-0.23	-0.0431
23	0	Correlation	-0.2323	-0.3586	-0.1263
24	20	Biased	-0.0414	-0.4148	-0.3734
26	50	Biased	-0.1463	-0.3368	-0.1905
27	30	Unbiased	-0.1261	-0.1644	-0.0383
28	30	Biased	-0.0601	1.0078	1.0679
29	30	Unbiased	-0.2691	0.911	1.1801
30	20	Biased	-0.1619	-0.1829	-0.021
31	30	Unbiased	-0.1105	-0.3274	-0.2169
33	30	Biased	-0.2785	-0.3358	-0.0573
34	50	Unbiased	-0.0621	1.0047	1.0668
35	20	Unbiased	-0.0511	-0.3015	-0.2504
41	30	Biased	-0.1197	1.4712	1.5909

Test Statistics (nA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.2347	-0.1647	-0.0508	0.087568	-0.3804	0.007425	0.9454	0.63195	-0.1457	0.17213	1.0864	0.60959
20	-0.3097	-0.12226	-0.0098	0.085294	-0.4553	-0.07063	0.9797	0.5453	-0.3734	0.05163	1.1323	0.55515
30	-0.2785	-0.15409	-0.0601	0.071796	-0.3742	0.14708	1.4712	0.69602	-0.261	0.30117	1.5909	0.69211
50	-0.2441	-0.12823	-0.0476	0.069759	-0.3368	0.24015	1.011	0.64155	-0.1905	0.36838	1.1496	0.60392

Device Test: 19.13 LEVEL|TRANSCONDUCTANCE//14/14/0/0/5/500kHz//@EA_GM





Test Results (Lower Limit = 1100.0, Upper Limit = 2700.0 (µA/V))

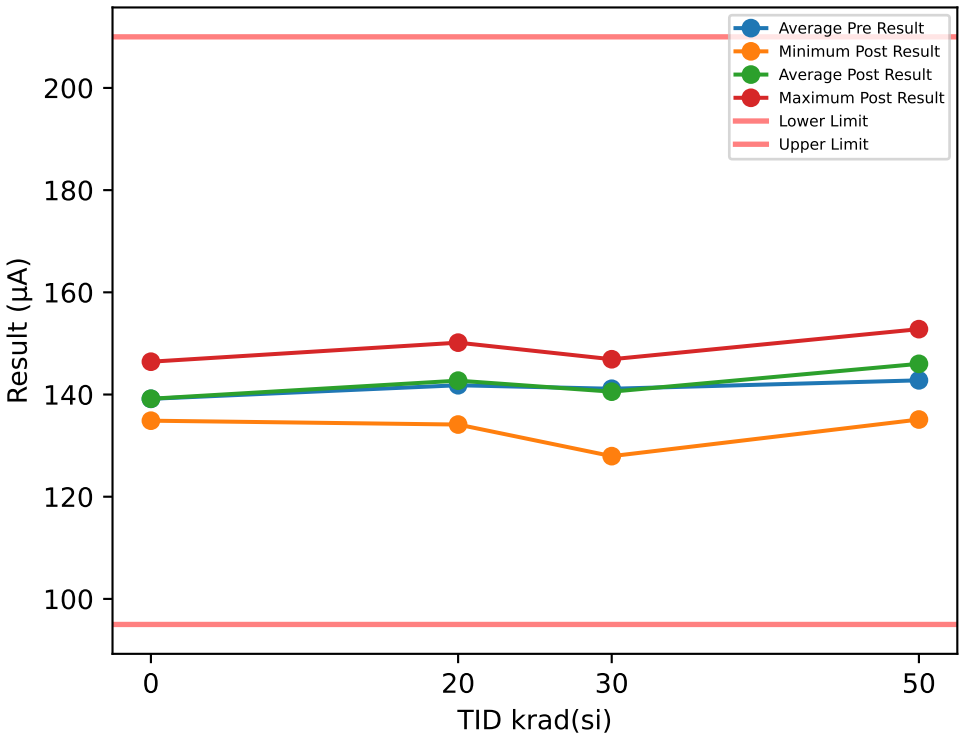
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	1720.8	1738.1	17.3
2	20	Unbiased	1798.8	1757.2	-41.645
3	50	Biased	1701.7	1648.5	-53.229
4	30	Unbiased	1740.7	1799	58.331
5	50	Unbiased	1684.5	1779	94.436
6	30	Biased	1685.2	1721.6	36.392
7	50	Biased	1838.6	1796.6	-41.968
8	30	Unbiased	1740.7	1779.2	38.451
9	20	Unbiased	1667	1703.3	36.362
10	50	Biased	1778.8	1779	0.1603
11	30	Biased	1649.1	1703.3	54.21
12	0	Correlation	1759.8	1779	19.146
13	0	Correlation	1667	1665.6	-1.3571
14	50	Unbiased	1883.4	1840.4	-43.036
15	20	Biased	1777.3	1759.4	-17.893
16	20	Unbiased	1617.6	1650.8	33.13
17	20	Biased	1739.5	1799.1	59.673
18	20	Unbiased	1798.8	1840.5	41.707
19	20	Biased	1701.7	1757.2	55.464
20	50	Unbiased	1703.7	1840.4	136.73
21	0	Correlation	1702.5	1703.5	0.9939
22	50	Unbiased	1703.1	1779.1	75.942
23	0	Correlation	1615.8	1633.9	18.151
24	20	Biased	1703.7	1721.8	18.096
26	50	Biased	1703.1	1779.2	76.046
27	30	Unbiased	1777.3	1840.4	63.072
28	30	Biased	1799.4	1817.1	17.686
29	30	Unbiased	1684.5	1701.1	16.542
30	20	Biased	1703.1	1721.6	18.49
31	30	Unbiased	1632.2	1685.5	53.278
33	30	Biased	1720.8	1759.4	38.672
34	50	Unbiased	1740.1	1796.6	56.492
35	20	Unbiased	1666.2	1685.3	19.107
41	30	Biased	1759.3	1551.8	-207.47

Test Statistics (µA/V)

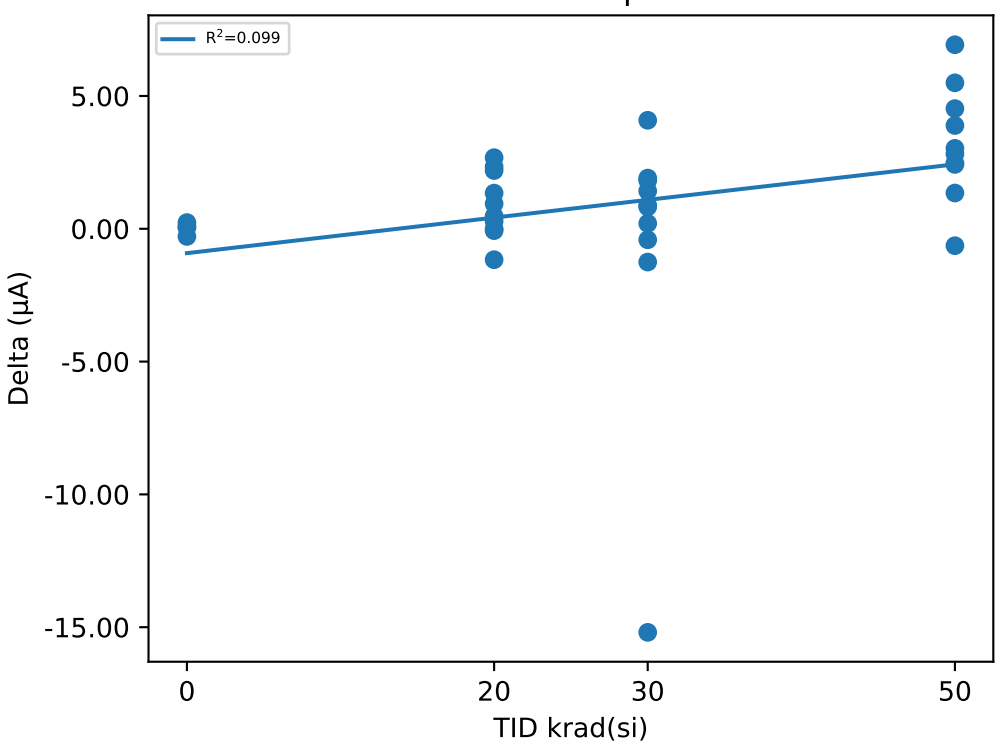
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1615.8	1686.3	1759.8	60.602	1633.9	1695.5	1779	62.497	-1.3571	9.2334	19.146	10.921
20	1617.6	1717.4	1798.8	60.631	1650.8	1739.6	1840.5	55.309	-41.645	22.249	59.673	31.509
30	1632.2	1718.9	1799.4	54.956	1551.8	1735.8	1840.4	83.544	-207.47	16.917	63.072	80.431
50	1684.5	1745.8	1883.4	67.019	1648.5	1777.7	1840.4	54.63	-53.229	31.887	136.73	65.771

Device Test: 19.14 CURRENT|EA_SOURCE//14/14/0/0/5/500kHz//@EA_I_SOURCE

TID vs Result Stats



TID vs Post - Pre Exposure Delta



Test Results (Lower Limit = 95.0, Upper Limit = 210.0 (µA))

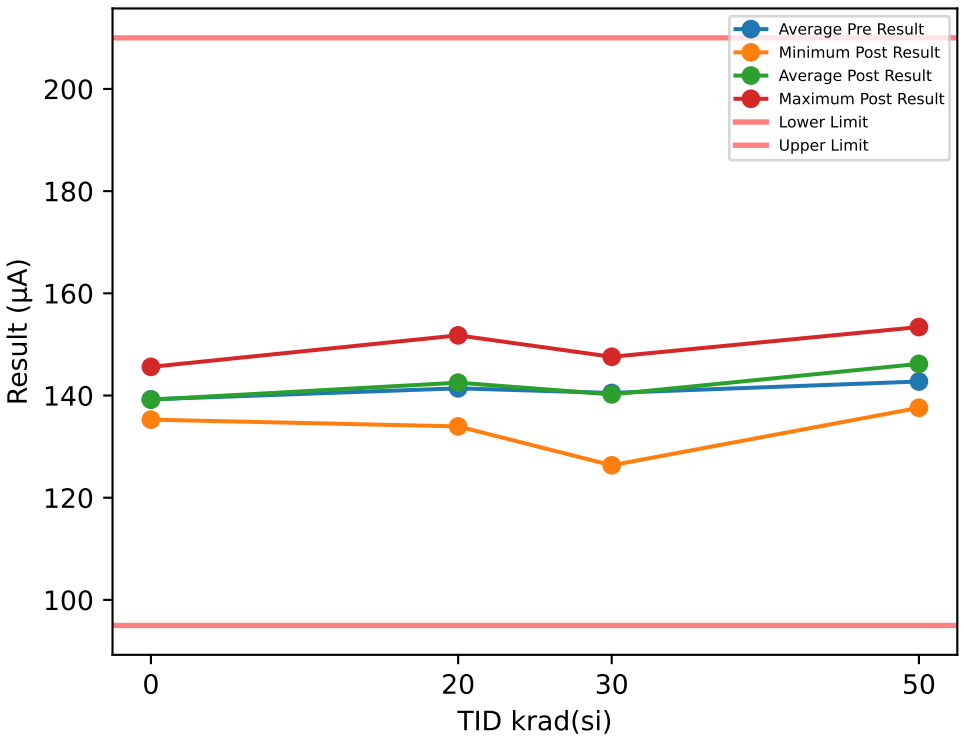
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	140.8	142.14	1.3466
2	20	Unbiased	146.29	146.76	0.4766
3	50	Biased	135.74	135.11	-0.637
4	30	Unbiased	144.99	146.9	1.9089
5	50	Unbiased	141.83	146.36	4.5254
6	30	Biased	137.78	136.52	-1.253
7	50	Biased	150.32	152.79	2.477
8	30	Unbiased	143.49	144.37	0.8837
9	20	Unbiased	135.46	137.79	2.336
10	50	Biased	145.78	148.81	3.0278
11	30	Biased	139.54	139.13	-0.4134
12	0	Correlation	146.38	146.42	0.046
13	0	Correlation	135.52	135.23	-0.288
14	50	Unbiased	146.6	149.42	2.8158
15	20	Biased	144.22	143.06	-1.1643
16	20	Unbiased	133.18	134.12	0.9454
17	20	Biased	144.97	146.32	1.3428
18	20	Unbiased	149.87	150.15	0.2862
19	20	Biased	145.48	147.67	2.193
20	50	Unbiased	142.29	146.18	3.8887
21	0	Correlation	140.08	140.16	0.0831
22	50	Unbiased	141.89	148.82	6.9293
23	0	Correlation	134.65	134.88	0.2338
24	20	Biased	142.42	142.42	0.0038
26	50	Biased	139.38	144.87	5.495
27	30	Unbiased	146.01	146.84	0.8258
28	30	Biased	145.25	146.67	1.4227
29	30	Unbiased	134.74	136.55	1.8166
30	20	Biased	139.91	142.59	2.6772
31	30	Unbiased	135.43	135.63	0.2029
33	30	Biased	140.92	145.01	4.0848
34	50	Unbiased	143.11	145.54	2.423
35	20	Unbiased	136.34	136.27	-0.07
41	30	Biased	143.13	127.94	-15.195

Test Statistics (µA)

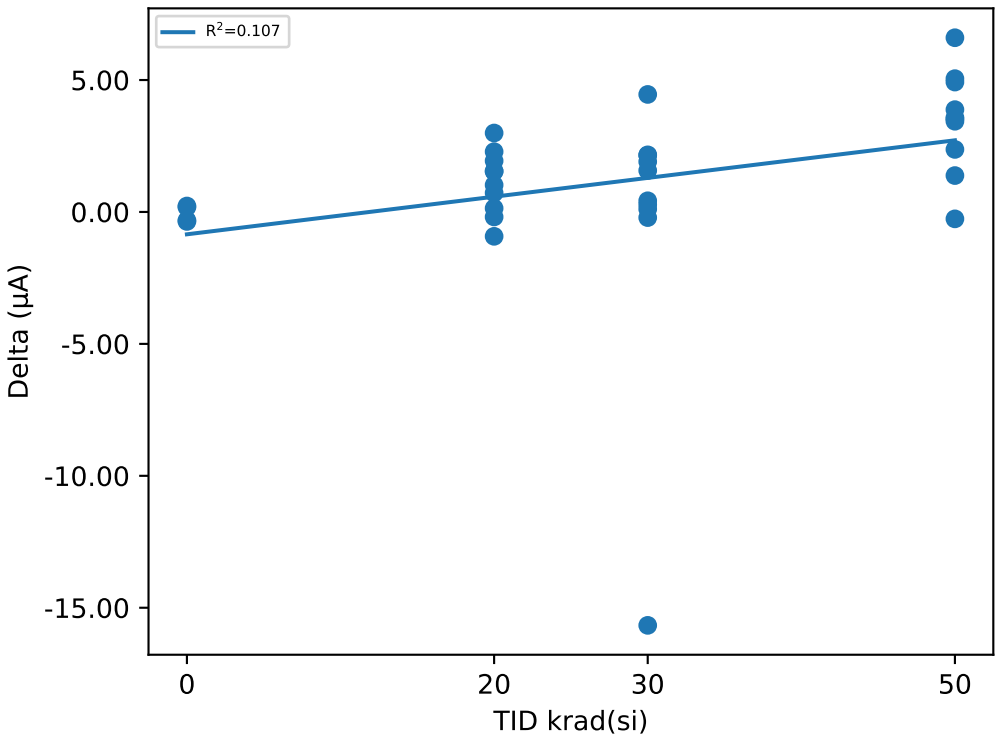
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	134.65	139.15	146.38	5.3708	134.88	139.17	146.42	5.4001	-0.288	0.018725	0.2338	0.22002
20	133.18	141.81	149.87	5.4052	134.12	142.72	150.15	5.2598	-1.1643	0.90267	2.6772	1.2316
30	134.74	141.13	146.01	4.1158	127.94	140.56	146.9	6.4051	-15.195	-0.57155	4.0848	5.3386
50	135.74	142.77	150.32	4.0477	135.11	146	152.79	4.8169	-0.637	3.2292	6.9293	2.1307

Device Test: 19.15 CURRENT|EA_SINK//14/14/0/0/5/500kHz//@EA_I_SINK

TID vs Result Stats



TID vs Post - Pre Exposure Delta



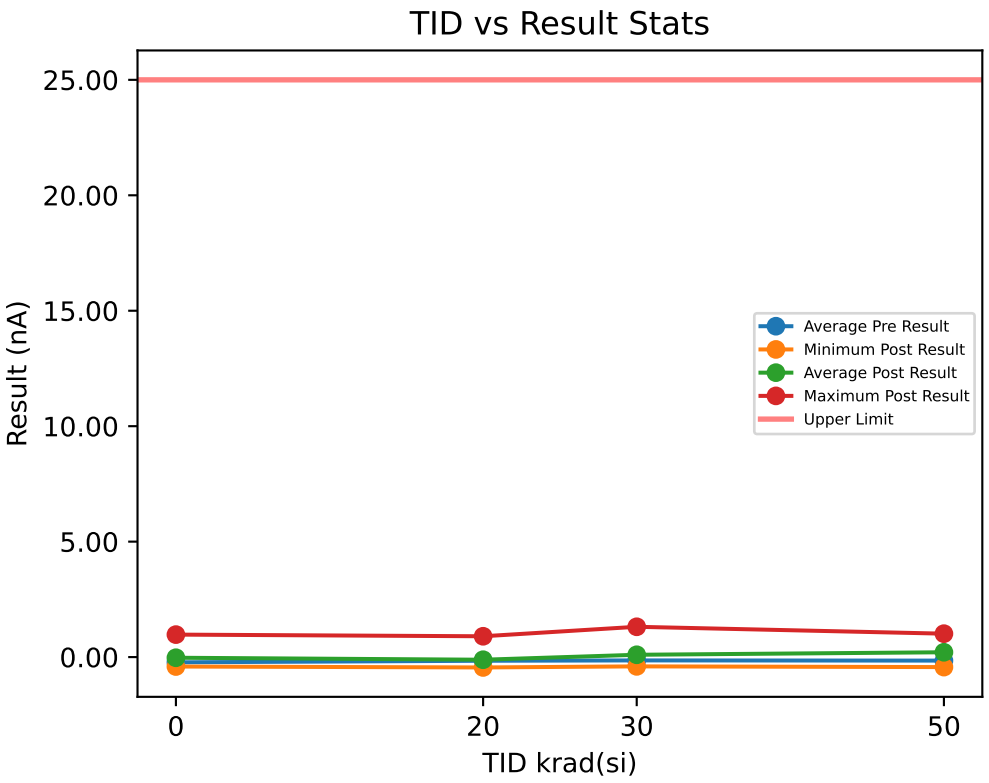
Test Results (Lower Limit = 95.0, Upper Limit = 210.0 (µA))

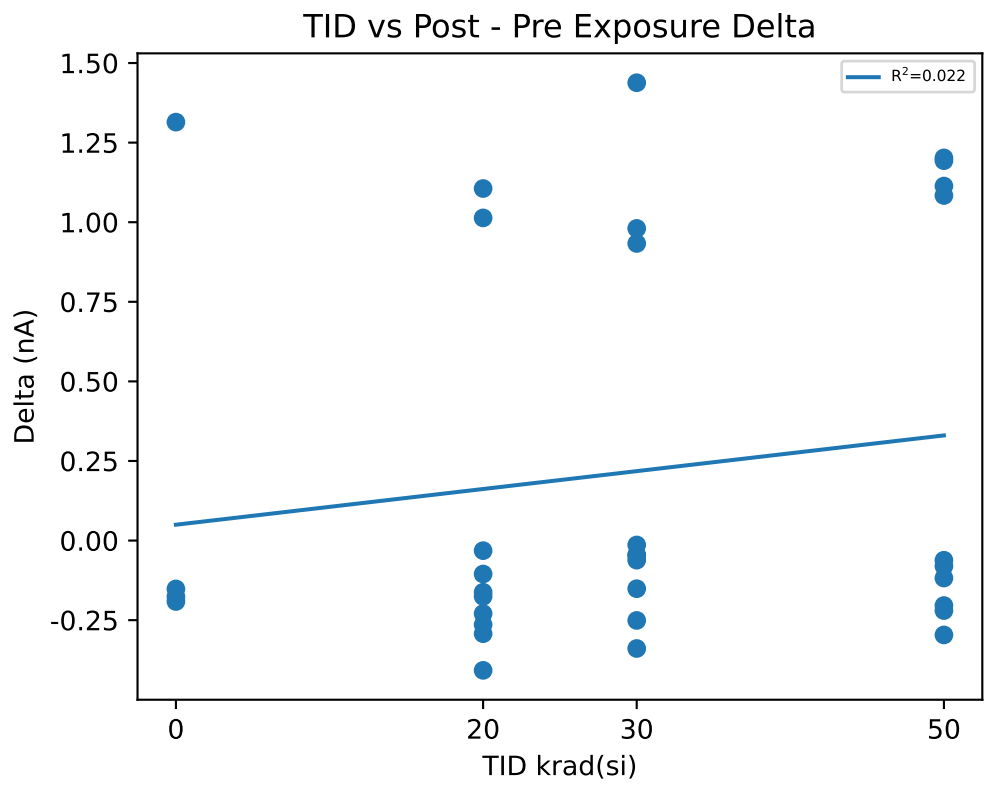
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	140.62	141.99	1.3794
2	20	Unbiased	145.87	146.9	1.0207
3	50	Biased	137.86	137.6	-0.2617
4	30	Unbiased	145.43	147.58	2.1489
5	50	Unbiased	140.74	145.79	5.0518
6	30	Biased	138.71	138.5	-0.2134
7	50	Biased	149.82	153.4	3.574
8	30	Unbiased	142.44	144.01	1.5705
9	20	Unbiased	135.02	136.96	1.9375
10	50	Biased	145.28	149.16	3.8777
11	30	Biased	137.54	137.65	0.1086
12	0	Correlation	145.96	145.6	-0.3592
13	0	Correlation	135.97	135.65	-0.3179
14	50	Unbiased	146.72	150.25	3.5255
15	20	Biased	144.61	143.69	-0.9235
16	20	Unbiased	133.24	133.96	0.721
17	20	Biased	144.07	145.62	1.5473
18	20	Unbiased	150.24	151.78	1.5374
19	20	Biased	144.7	146.99	2.2847
20	50	Unbiased	142.38	145.82	3.4379
21	0	Correlation	139.99	140.21	0.2253
22	50	Unbiased	143.02	149.62	6.6026
23	0	Correlation	135.09	135.28	0.184
24	20	Biased	141.56	141.38	-0.1893
26	50	Biased	138.46	143.39	4.9226
27	30	Unbiased	146.34	146.76	0.4236
28	30	Biased	145.37	147.27	1.9058
29	30	Unbiased	134.02	136.18	2.1634
30	20	Biased	138.43	141.42	2.992
31	30	Unbiased	133.62	133.9	0.2773
33	30	Biased	139.52	143.97	4.4539
34	50	Unbiased	142.51	144.88	2.3702
35	20	Unbiased	136.32	136.46	0.1392
41	30	Biased	142.01	126.35	-15.667

Test Statistics (µA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	135.09	139.25	145.96	4.955	135.28	139.19	145.6	4.8312	-0.3592	-0.06695	0.2253	0.31452
20	133.24	141.41	150.24	5.4612	133.96	142.51	151.78	5.5697	-0.9235	1.1067	2.992	1.1975
30	133.62	140.5	146.34	4.5991	126.35	140.22	147.58	6.9399	-15.667	-0.28288	4.4539	5.5799
50	137.86	142.74	149.82	3.7023	137.6	146.19	153.4	4.5981	-0.2617	3.448	6.6026	1.9467

Device Test: 19.16 CURRENT|EA//14/14/0/0/5/500kHz//@EA_IB





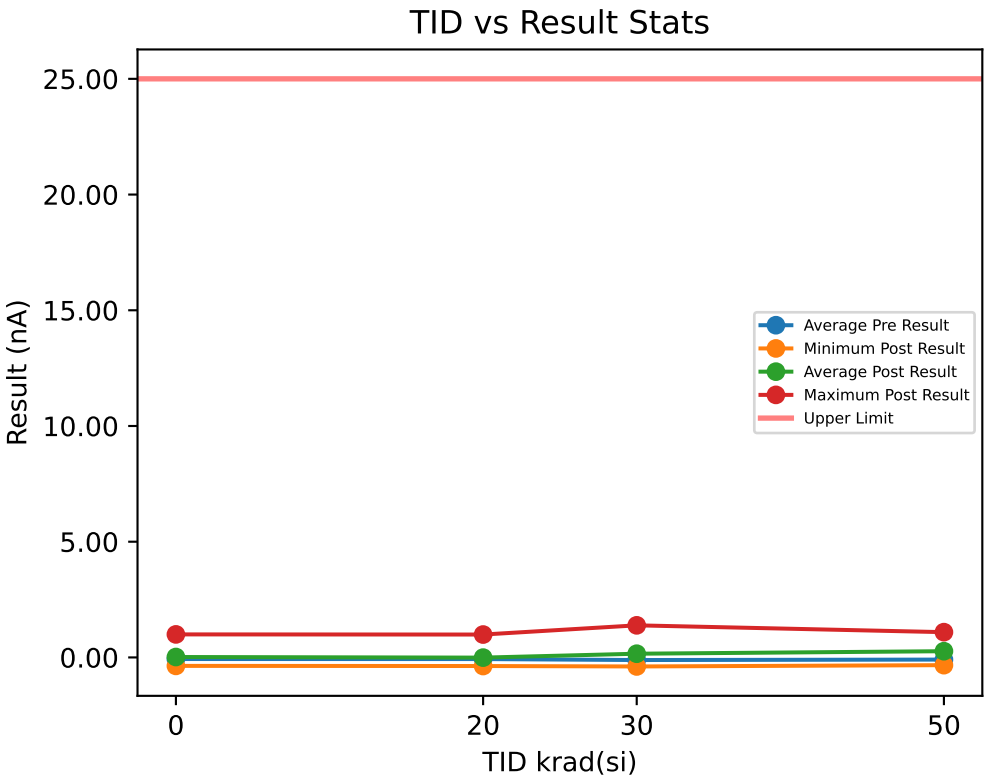
Test Results (Upper Limit = 25.0 (nA))

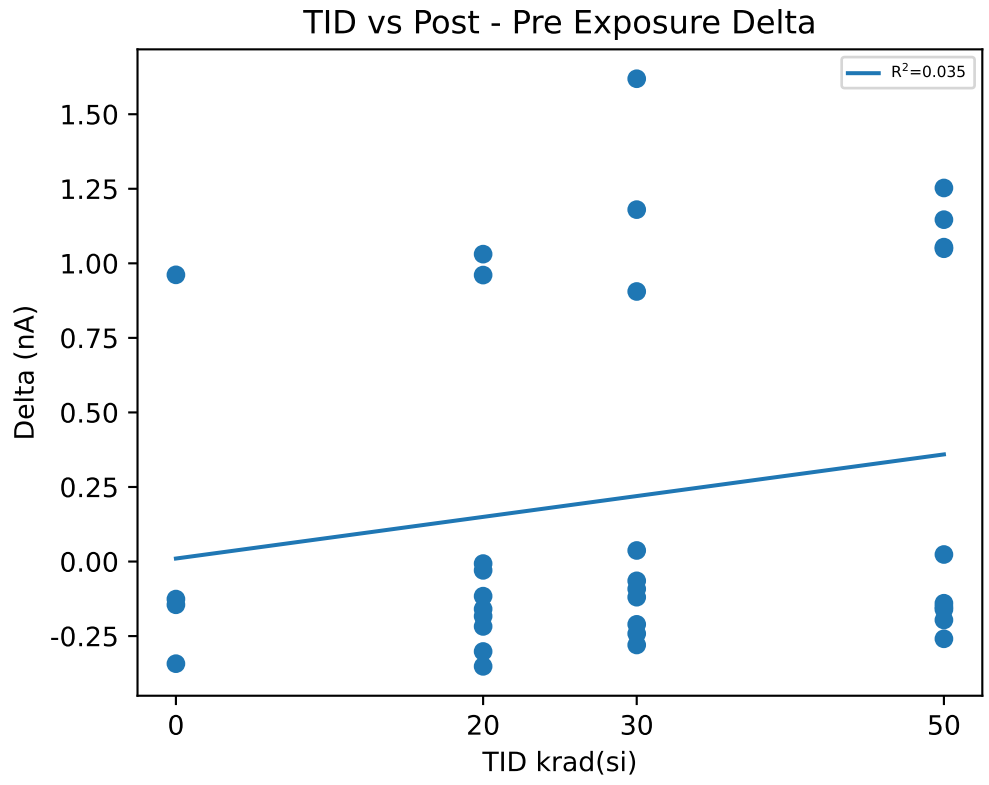
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	-0.1879	1.0141	1.202
2	20	Unbiased	-0.1744	0.8391	1.0135
3	50	Biased	-0.198	0.9953	1.1933
4	30	Unbiased	-0.0695	-0.3204	-0.2509
5	50	Unbiased	-0.0879	-0.3078	-0.2199
6	30	Biased	-0.1432	-0.2048	-0.0616
7	50	Biased	-0.1167	0.9672	1.0839
8	30	Unbiased	-0.0633	-0.4023	-0.339
9	20	Unbiased	-0.0723	-0.3017	-0.2294
10	50	Biased	-0.24	-0.3577	-0.1177
11	30	Biased	-0.3011	-0.3452	-0.0441
12	0	Correlation	-0.1101	-0.3015	-0.1914
13	0	Correlation	-0.3409	0.9735	1.3144
14	50	Unbiased	-0.1619	-0.2237	-0.0618
15	20	Biased	-0.2511	-0.2828	-0.0317
16	20	Unbiased	-0.1069	-0.3711	-0.2642
17	20	Biased	-0.3409	-0.446	-0.1051
18	20	Unbiased	-0.2618	-0.4241	-0.1623
19	20	Biased	-0.2042	0.9016	1.1058
20	50	Unbiased	-0.0695	-0.2736	-0.2041
21	0	Correlation	-0.2566	-0.4085	-0.1519
22	50	Unbiased	-0.2181	-0.2986	-0.0805
23	0	Correlation	-0.2011	-0.3773	-0.1762
24	20	Biased	-0.0414	-0.4491	-0.4077
26	50	Biased	-0.137	-0.4335	-0.2965
27	30	Unbiased	-0.2198	-0.2674	-0.0476
28	30	Biased	-0.1257	0.8548	0.9805
29	30	Unbiased	0.0152	0.9485	0.9333
30	20	Biased	-0.0433	-0.3358	-0.2925
31	30	Unbiased	-0.2448	-0.396	-0.1512
33	30	Biased	-0.1629	-0.1767	-0.0138
34	50	Unbiased	-0.1058	1.0078	1.1136
35	20	Unbiased	-0.098	-0.2734	-0.1754
41	30	Biased	-0.1259	1.3122	1.4381

Test Statistics (nA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.3409	-0.22717	-0.1101	0.096929	-0.4085	-0.02845	0.9735	0.66948	-0.1914	0.19872	1.3144	0.74396
20	-0.3409	-0.15943	-0.0414	0.10306	-0.4491	-0.11433	0.9016	0.52313	-0.4077	0.0451	1.1058	0.54498
30	-0.3011	-0.1441	0.0152	0.093698	-0.4023	0.10027	1.3122	0.66138	-0.339	0.24437	1.4381	0.62471
50	-0.24	-0.15228	-0.0695	0.057866	-0.4335	0.20895	1.0141	0.67972	-0.2965	0.36123	1.202	0.68158

Device Test: 19.17 CURRENT|EA//4.5/4.5/0/0/4.5/100kHz//@EA_IB





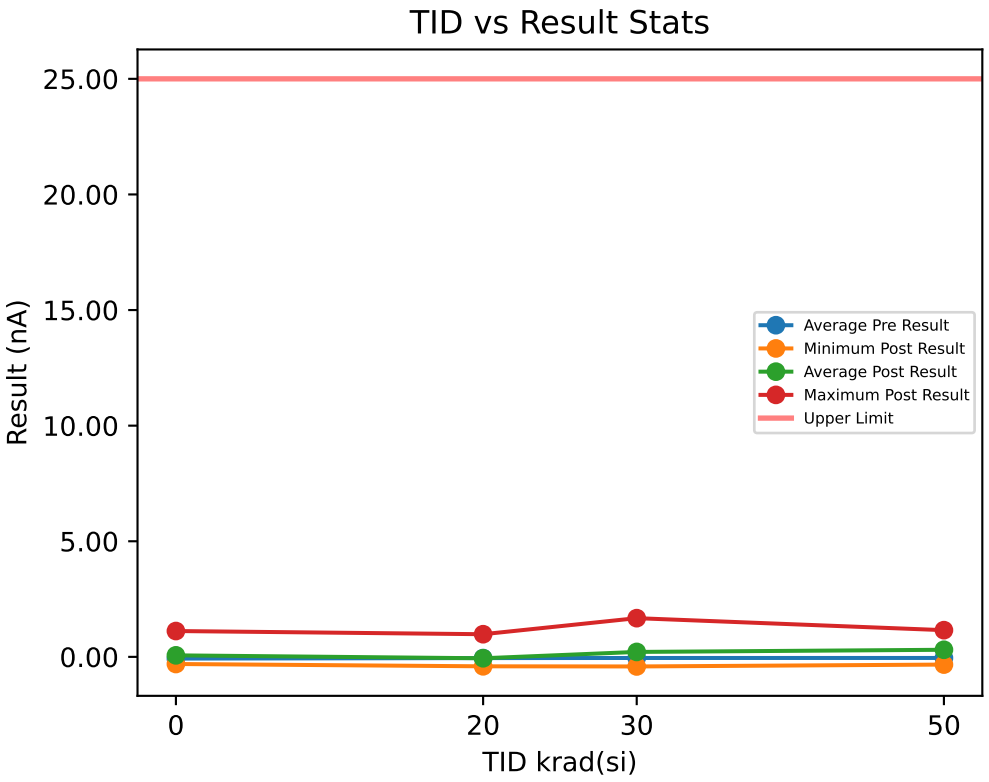
Test Results (Upper Limit = 25.0 (nA))

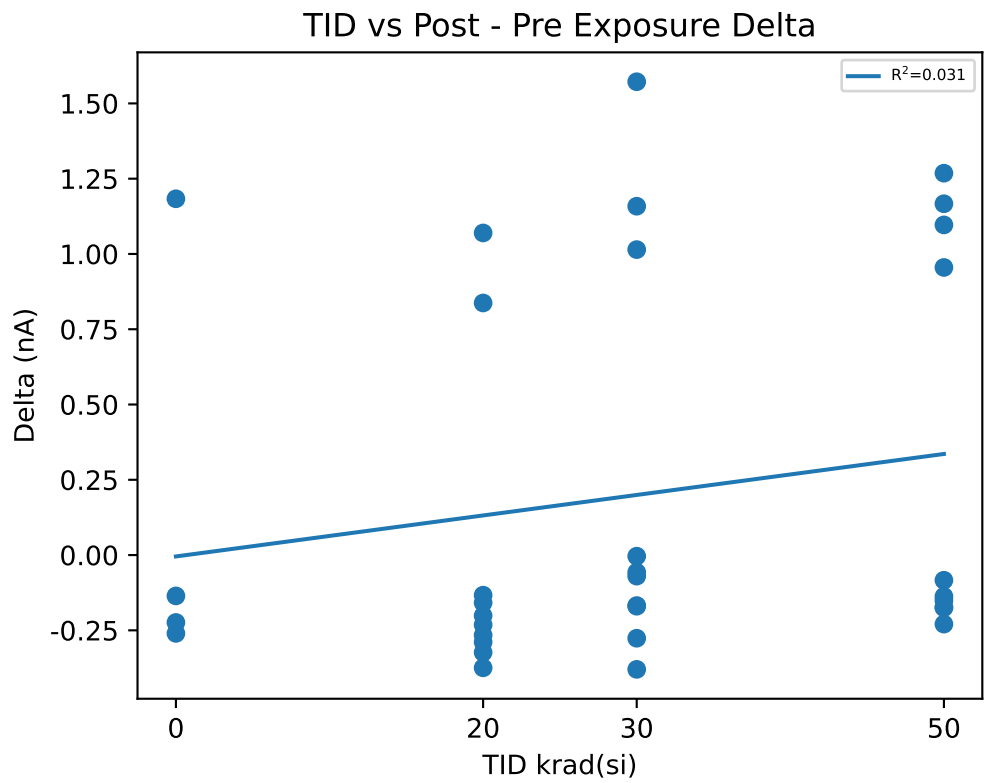
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	-0.1285	0.9204	1.0489
2	20	Unbiased	0.0285	0.9891	0.9606
3	50	Biased	-0.1261	1.0203	1.1464
4	30	Unbiased	-0.0508	-0.1426	-0.0918
5	50	Unbiased	-0.1566	-0.133	0.0236
6	30	Biased	-0.1307	-0.1954	-0.0647
7	50	Biased	-0.1605	1.0922	1.2527
8	30	Unbiased	-0.0445	-0.3243	-0.2798
9	20	Unbiased	-0.1723	-0.2019	-0.0296
10	50	Biased	-0.0527	-0.2048	-0.1521
11	30	Biased	-0.298	-0.2609	0.0371
12	0	Correlation	-0.0664	-0.1923	-0.1259
13	0	Correlation	0.0339	0.9953	0.9614
14	50	Unbiased	-0.1089	-0.2487	-0.1398
15	20	Biased	-0.1105	-0.2266	-0.1161
16	20	Unbiased	-0.032	-0.3336	-0.3016
17	20	Biased	-0.0942	-0.2775	-0.1833
18	20	Unbiased	-0.1182	-0.2775	-0.1593
19	20	Biased	-0.0636	0.9672	1.0308
20	50	Unbiased	-0.0539	-0.2144	-0.1605
21	0	Correlation	-0.0223	-0.3648	-0.3425
22	50	Unbiased	-0.0215	-0.2175	-0.196
23	0	Correlation	-0.2198	-0.3648	-0.145
24	20	Biased	-0.0196	-0.3711	-0.3515
26	50	Biased	-0.0745	-0.3336	-0.2591
27	30	Unbiased	-0.0355	-0.1551	-0.1196
28	30	Biased	0.0304	0.936	0.9056
29	30	Unbiased	-0.2722	0.9079	1.1801
30	20	Biased	0.0222	-0.1954	-0.2176
31	30	Unbiased	-0.148	-0.3898	-0.2418
33	30	Biased	0.0558	-0.1548	-0.2106
34	50	Unbiased	-0.0433	1.011	1.0543
35	20	Unbiased	-0.1449	-0.1517	-0.0068
41	30	Biased	-0.232	1.387	1.619

Test Statistics (nA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.2198	-0.06865	0.0339	0.10881	-0.3648	0.01835	0.9953	0.65636	-0.3425	0.087	0.9614	0.5911
20	-0.1723	-0.07046	0.0285	0.069001	-0.3711	-0.0079	0.9891	0.52382	-0.3515	0.06256	1.0308	0.50348
30	-0.298	-0.11255	0.0558	0.12423	-0.3898	0.1608	1.387	0.64956	-0.2798	0.27335	1.619	0.6909
50	-0.1605	-0.09265	-0.0215	0.049762	-0.3336	0.26919	1.0922	0.64158	-0.2591	0.36184	1.2527	0.66337

Device Test: 19.18 CURRENT|EA//4.5/4.5/0/0/4.5/1MHz//@EA_IB





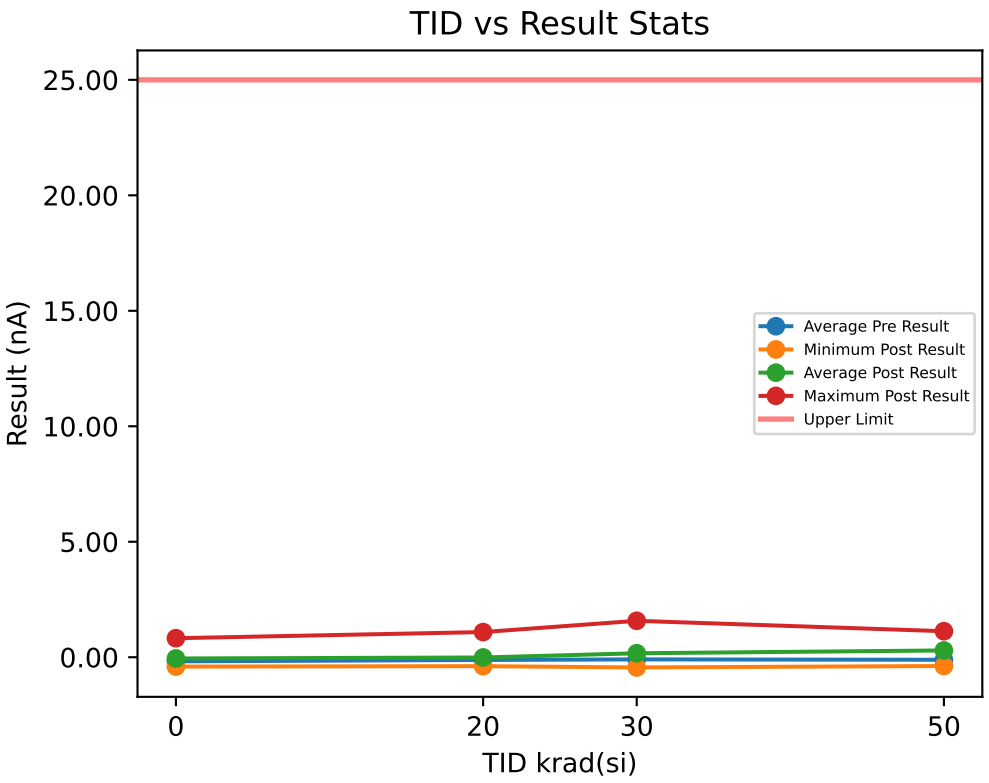
Test Results (Upper Limit = 25.0 (nA))

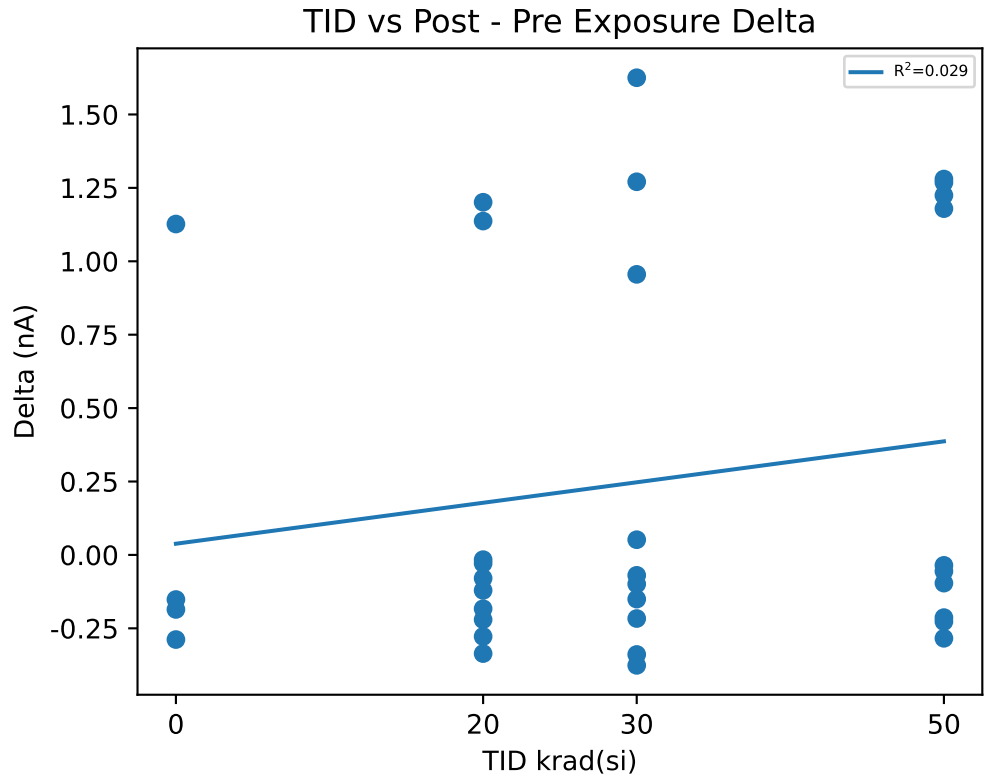
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	0.037	0.9922	0.9552
2	20	Unbiased	-0.0901	0.9797	1.0698
3	50	Biased	-0.0855	1.011	1.0965
4	30	Unbiased	-0.0445	-0.2144	-0.1699
5	50	Unbiased	0.0807	-0.1486	-0.2293
6	30	Biased	0.0066	-0.1611	-0.1677
7	50	Biased	-0.1199	1.1484	1.2683
8	30	Unbiased	-0.0008	-0.3804	-0.3796
9	20	Unbiased	0.0027	-0.1987	-0.2014
10	50	Biased	-0.0308	-0.2048	-0.174
11	30	Biased	-0.1917	-0.1954	-0.0037
12	0	Correlation	0.0116	-0.2485	-0.2601
13	0	Correlation	-0.0661	1.1172	1.1833
14	50	Unbiased	-0.0308	-0.205	-0.1742
15	20	Biased	-0.0355	-0.3015	-0.266
16	20	Unbiased	-0.004	-0.3274	-0.3234
17	20	Biased	-0.2597	-0.3929	-0.1332
18	20	Unbiased	-0.034	-0.4085	-0.3745
19	20	Biased	-0.0449	0.7923	0.8372
20	50	Unbiased	-0.004	-0.1551	-0.1511
21	0	Correlation	-0.0723	-0.2962	-0.2239
22	50	Unbiased	-0.1089	-0.1925	-0.0836
23	0	Correlation	-0.173	-0.3087	-0.1357
24	20	Biased	-0.0196	-0.3087	-0.2891
26	50	Biased	-0.1963	-0.3336	-0.1373
27	30	Unbiased	-0.0761	-0.1332	-0.0571
28	30	Biased	-0.0508	1.1078	1.1586
29	30	Unbiased	-0.0067	1.0078	1.0145
30	20	Biased	-0.0433	-0.2016	-0.1583
31	30	Unbiased	-0.1386	-0.4148	-0.2762
33	30	Biased	-0.0848	-0.1548	-0.07
34	50	Unbiased	-0.0121	1.1547	1.1668
35	20	Unbiased	-0.0043	-0.236	-0.2317
41	30	Biased	0.1019	1.6739	1.572

Test Statistics (nA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.173	-0.07495	0.0116	0.075697	-0.3087	0.06595	1.1172	0.70131	-0.2601	0.1409	1.1833	0.69689
20	-0.2597	-0.05327	0.0027	0.077401	-0.4085	-0.06033	0.9797	0.5057	-0.3745	-0.00706	1.0698	0.51436
30	-0.1917	-0.04855	0.1019	0.081924	-0.4148	0.21354	1.6739	0.74962	-0.3796	0.26209	1.572	0.70249
50	-0.1963	-0.04706	0.0807	0.081564	-0.3336	0.30667	1.1547	0.66639	-0.2293	0.35373	1.2683	0.66628

Device Test: 19.19 CURRENT|EA//5/5/0/0/5/100kHz//@EA_IB





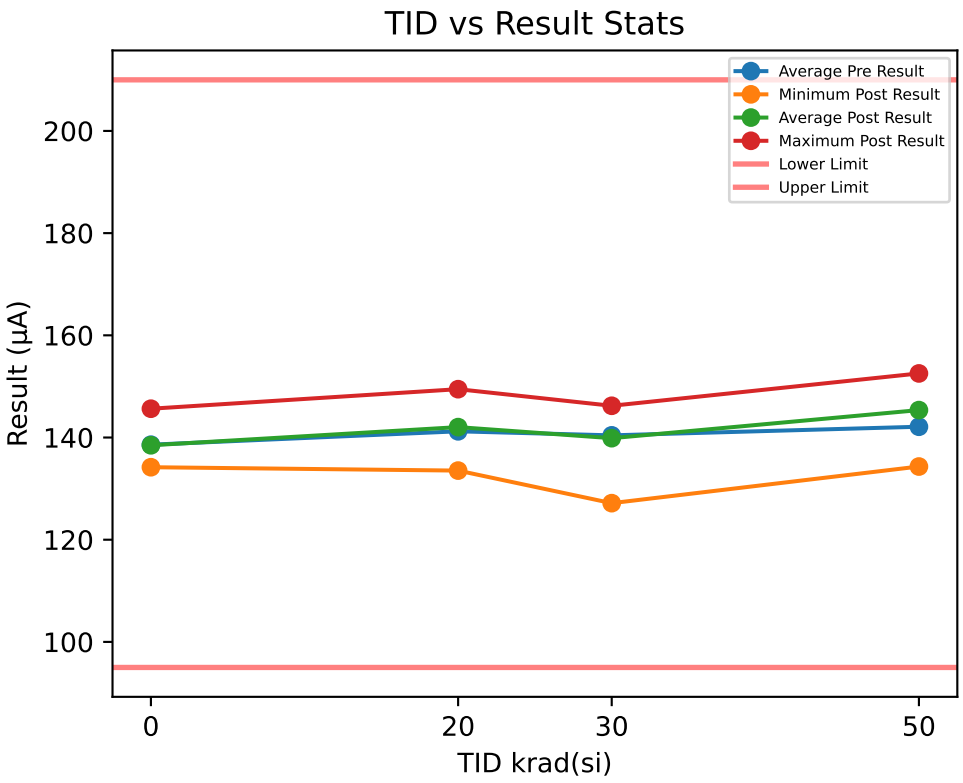
Test Results (Upper Limit = 25.0 (nA))

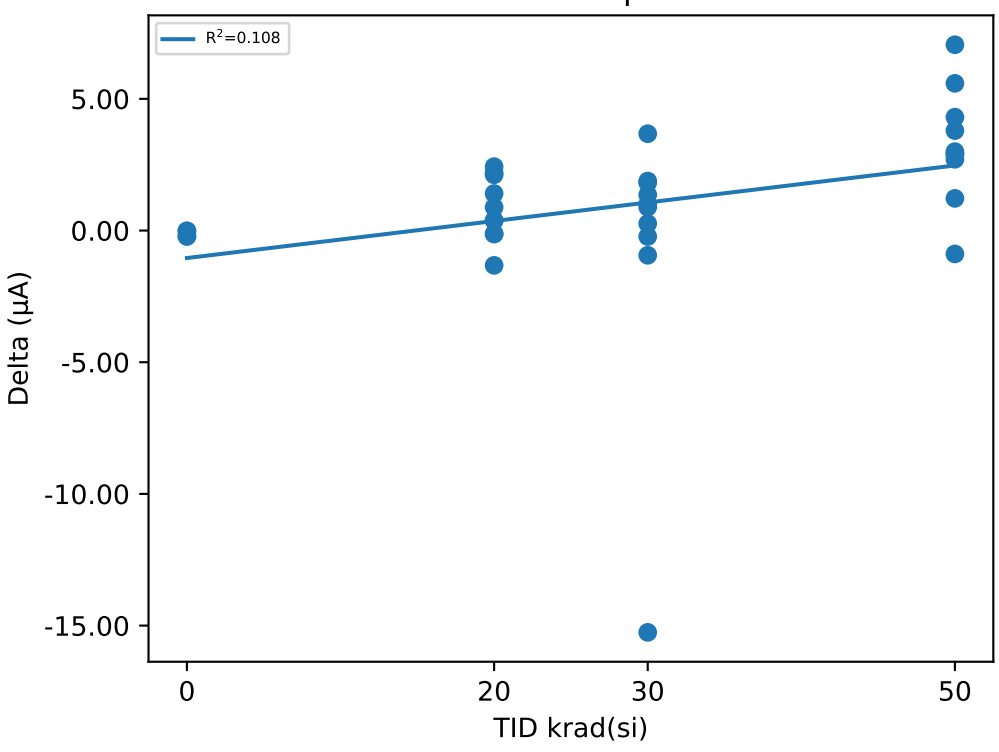
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	-0.2129	1.0672	1.2801
2	20	Unbiased	-0.112	1.0891	1.2011
3	50	Biased	-0.1699	1.0984	1.2683
4	30	Unbiased	-0.0258	-0.2424	-0.2166
5	50	Unbiased	-0.241	-0.2765	-0.0355
6	30	Biased	-0.0496	-0.1486	-0.099
7	50	Biased	-0.148	1.0766	1.2246
8	30	Unbiased	-0.1038	-0.4428	-0.339
9	20	Unbiased	-0.1317	-0.2112	-0.0795
10	50	Biased	-0.0496	-0.2765	-0.2269
11	30	Biased	-0.098	-0.2485	-0.1505
12	0	Correlation	-0.0071	-0.2953	-0.2882
13	0	Correlation	-0.3034	0.8235	1.1269
14	50	Unbiased	-0.0933	-0.1488	-0.0555
15	20	Biased	-0.1699	-0.186	-0.0161
16	20	Unbiased	-0.0476	-0.3836	-0.336
17	20	Biased	-0.2097	-0.3305	-0.1208
18	20	Unbiased	-0.1089	-0.3867	-0.2778
19	20	Biased	-0.0636	1.0734	1.137
20	50	Unbiased	0.0148	-0.1987	-0.2135
21	0	Correlation	-0.2535	-0.4054	-0.1519
22	50	Unbiased	-0.0527	-0.1488	-0.0961
23	0	Correlation	-0.1511	-0.3368	-0.1857
24	20	Biased	-0.1444	-0.3648	-0.2204
26	50	Biased	-0.0964	-0.3804	-0.284
27	30	Unbiased	-0.1667	-0.2362	-0.0695
28	30	Biased	-0.0445	0.911	0.9555
29	30	Unbiased	-0.0786	1.1922	1.2708
30	20	Biased	-0.0215	-0.2048	-0.1833
31	30	Unbiased	-0.0449	-0.421	-0.3761
33	30	Biased	-0.2753	-0.2235	0.0518
34	50	Unbiased	-0.0527	1.1266	1.1793
35	20	Unbiased	-0.1761	-0.2048	-0.0287
41	30	Biased	-0.0479	1.5772	1.6251

Test Statistics (nA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.3034	-0.17878	-0.0071	0.13084	-0.4054	-0.0535	0.8235	0.58643	-0.2882	0.12528	1.1269	0.67026
20	-0.2097	-0.11854	-0.0215	0.060283	-0.3867	-0.01099	1.0891	0.58111	-0.336	0.10755	1.2011	0.56901
30	-0.2753	-0.09351	-0.0258	0.076093	-0.4428	0.17174	1.5772	0.75022	-0.3761	0.26525	1.6251	0.73095
50	-0.241	-0.11017	0.0148	0.08099	-0.3804	0.29391	1.1266	0.69051	-0.284	0.40408	1.2801	0.72235

Device Test: 19.2 CURRENT|EA_SOURCE//4.5/4.5/0/0/4.5/500kHz//@EA_I_SOURCE





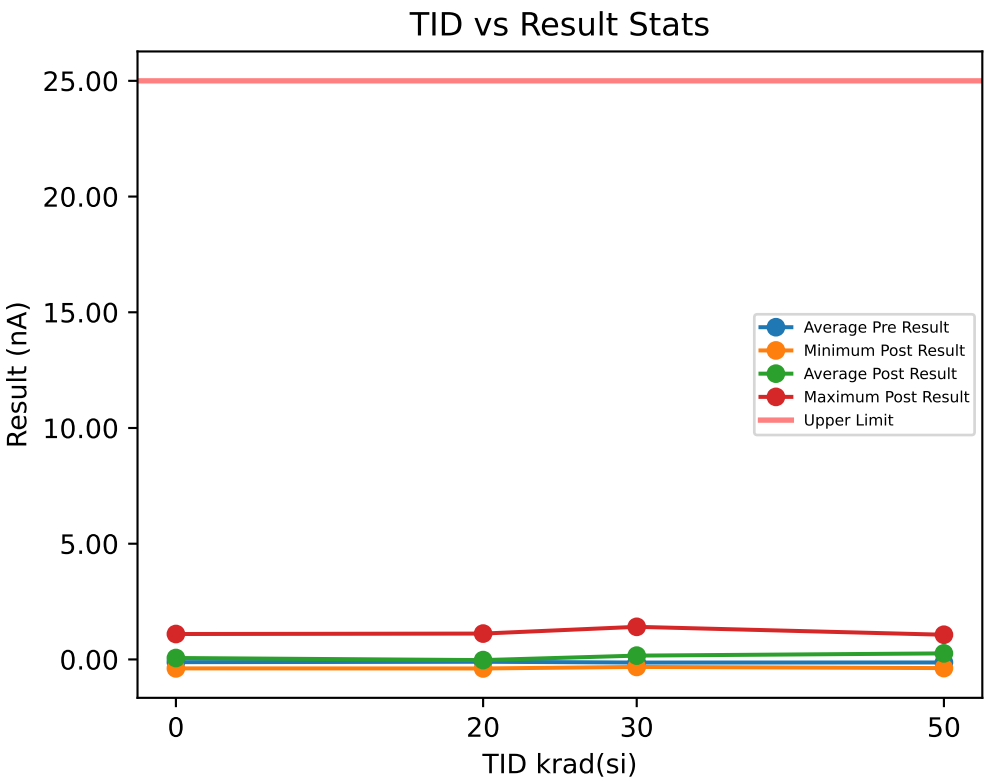
Test Results (Lower Limit = 95.0, Upper Limit = 210.0 (µA))

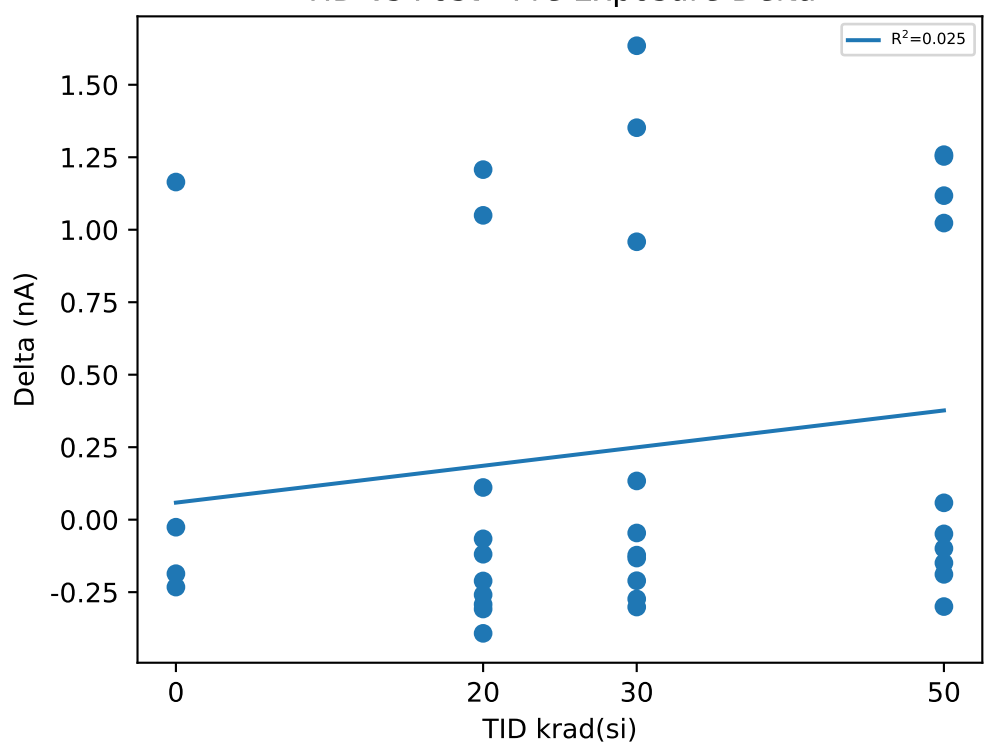
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	140.2	141.42	1.2208
2	20	Unbiased	145.88	146.26	0.3821
3	50	Biased	135.21	134.32	-0.8885
4	30	Unbiased	144.4	146.21	1.8149
5	50	Unbiased	141.39	145.7	4.3051
6	30	Biased	136.96	136.02	-0.9395
7	50	Biased	149.66	152.54	2.8852
8	30	Unbiased	142.7	143.71	1.0094
9	20	Unbiased	134.83	136.95	2.1161
10	50	Biased	145.03	148.03	2.9958
11	30	Biased	138.57	138.35	-0.2255
12	0	Correlation	145.84	145.64	-0.2055
13	0	Correlation	134.77	134.54	-0.2253
14	50	Unbiased	145.91	148.82	2.9099
15	20	Biased	143.5	142.18	-1.322
16	20	Unbiased	132.65	133.53	0.8825
17	20	Biased	144.32	145.72	1.4053
18	20	Unbiased	149.08	149.46	0.3799
19	20	Biased	144.85	147.04	2.1928
20	50	Unbiased	141.66	145.46	3.7948
21	0	Correlation	139.57	139.56	-0.0113
22	50	Unbiased	141.2	148.25	7.0548
23	0	Correlation	134.21	134.19	-0.0179
24	20	Biased	141.73	141.6	-0.122
26	50	Biased	138.59	144.18	5.5887
27	30	Unbiased	145.26	146.15	0.8886
28	30	Biased	144.52	145.88	1.36
29	30	Unbiased	134.33	136.21	1.8793
30	20	Biased	139.5	141.93	2.4255
31	30	Unbiased	134.8	135.07	0.2653
33	30	Biased	140.29	143.97	3.6759
34	50	Unbiased	142.23	144.94	2.7054
35	20	Unbiased	135.81	135.67	-0.1333
41	30	Biased	142.41	127.15	-15.257

Test Statistics (µA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	134.21	138.6	145.84	5.3974	134.19	138.48	145.64	5.364	-0.2253	-0.115	-0.0113	0.11624
20	132.65	141.21	149.08	5.3573	133.53	142.03	149.46	5.2769	-1.322	0.82069	2.4255	1.2137
30	134.33	140.42	145.26	4.0733	127.15	139.87	146.21	6.348	-15.257	-0.55282	3.6759	5.3199
50	135.21	142.11	149.66	4.0151	134.32	145.37	152.54	4.9222	-0.8885	3.2572	7.0548	2.1912

Device Test: 19.20 CURRENT|EA//5/5/0/0/5/1MHz//@EA_IB





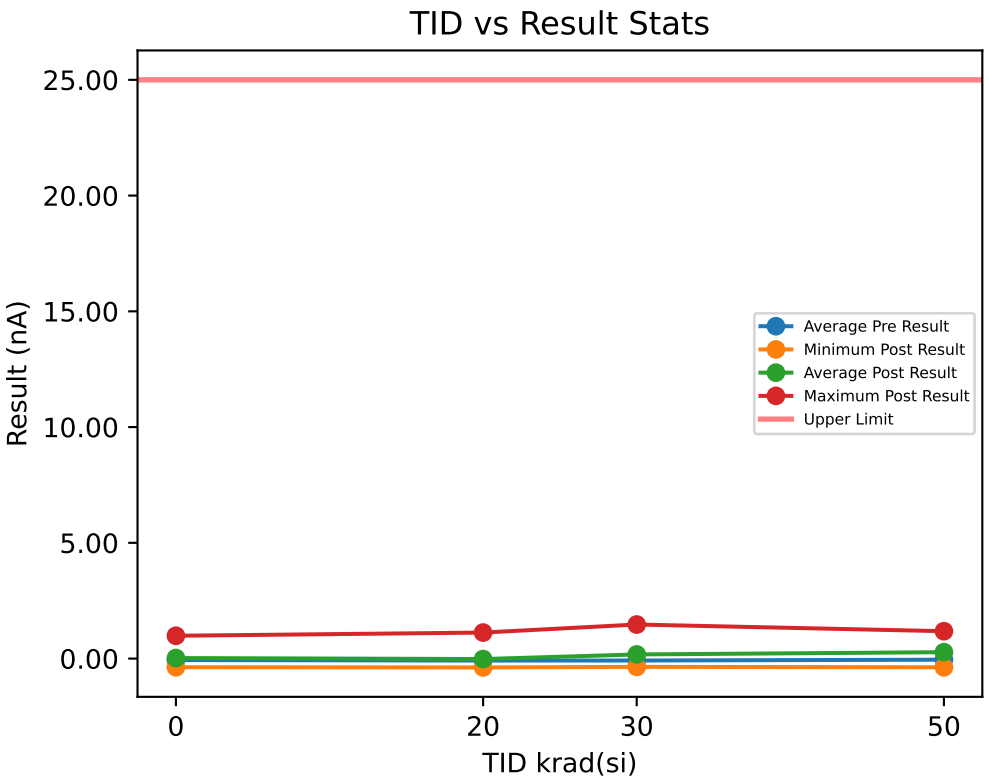
Test Results (Upper Limit = 25.0 (nA))

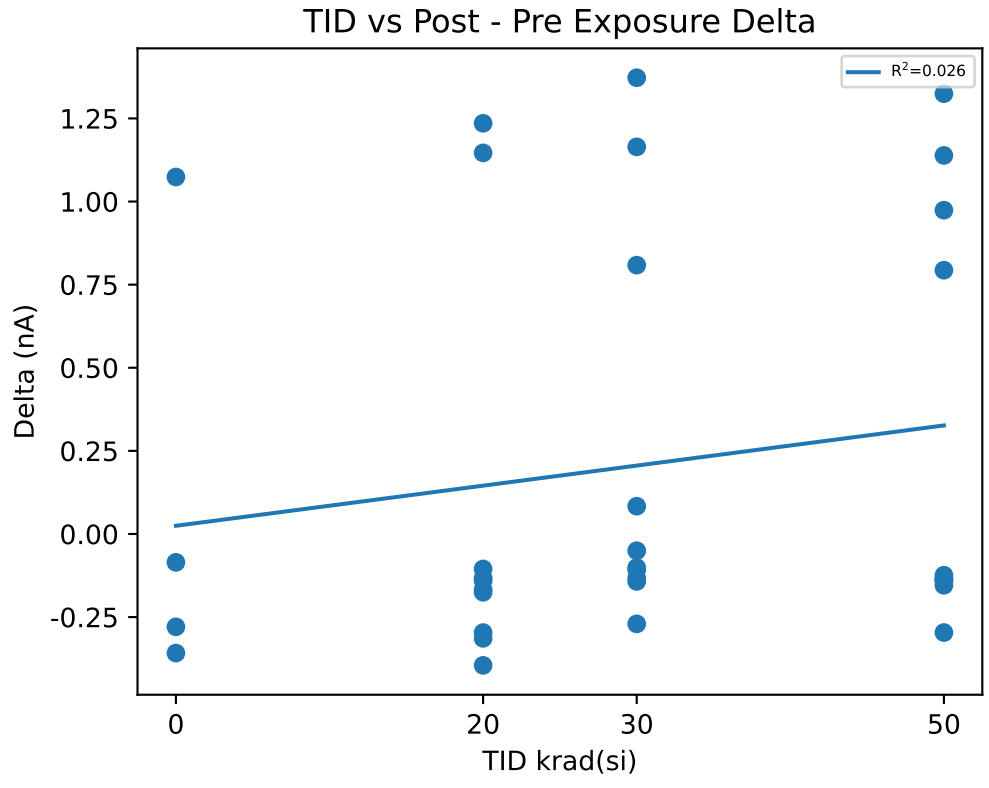
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	-0.1504	0.9672	1.1176
2	20	Unbiased	-0.0901	1.1172	1.2073
3	50	Biased	-0.2042	1.0547	1.2589
4	30	Unbiased	-0.0726	-0.205	-0.1324
5	50	Unbiased	-0.2597	-0.2016	0.0581
6	30	Biased	-0.1245	-0.1704	-0.0459
7	50	Biased	-0.1855	1.0672	1.2527
8	30	Unbiased	-0.0508	-0.3243	-0.2735
9	20	Unbiased	-0.291	-0.18	0.111
10	50	Biased	-0.0933	-0.1423	-0.049
11	30	Biased	-0.1199	-0.2422	-0.1223
12	0	Correlation	-0.0789	-0.1049	-0.026
13	0	Correlation	-0.0661	1.0984	1.1645
14	50	Unbiased	-0.1151	-0.2144	-0.0993
15	20	Biased	-0.1074	-0.2266	-0.1192
16	20	Unbiased	-0.0102	-0.3024	-0.2922
17	20	Biased	-0.0536	-0.3617	-0.3081
18	20	Unbiased	-0.1307	-0.3898	-0.2591
19	20	Biased	-0.0949	0.9547	1.0496
20	50	Unbiased	-0.057	-0.2456	-0.1886
21	0	Correlation	-0.2004	-0.3867	-0.1863
22	50	Unbiased	-0.112	-0.2612	-0.1492
23	0	Correlation	-0.1261	-0.3586	-0.2325
24	20	Biased	0.0148	-0.3773	-0.3921
26	50	Biased	-0.0745	-0.3742	-0.2997
27	30	Unbiased	-0.2855	-0.1519	0.1336
28	30	Biased	-0.1319	0.8266	0.9585
29	30	Unbiased	-0.3128	1.0391	1.3519
30	20	Biased	-0.0745	-0.2859	-0.2114
31	30	Unbiased	-0.0074	-0.3087	-0.3013
33	30	Biased	-0.013	-0.2235	-0.2105
34	50	Unbiased	-0.0589	0.9641	1.023
35	20	Unbiased	-0.1699	-0.236	-0.0661
41	30	Biased	-0.2258	1.4088	1.6346

Test Statistics (nA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.2004	-0.11787	-0.0661	0.060767	-0.3867	0.06205	1.0984	0.70243	-0.2325	0.17993	1.1645	0.66232
20	-0.291	-0.10075	0.0148	0.085977	-0.3898	-0.02878	1.1172	0.56657	-0.3921	0.07197	1.2073	0.57583
30	-0.3128	-0.13442	-0.0074	0.10801	-0.3243	0.16485	1.4088	0.65652	-0.3013	0.29927	1.6346	0.72915
50	-0.2597	-0.13106	-0.057	0.067635	-0.3742	0.26139	1.0672	0.65051	-0.2997	0.39245	1.2589	0.6727

Device Test: 19.21 CURRENT|EA//12/12/0/0/5/100kHz//@EA_IB





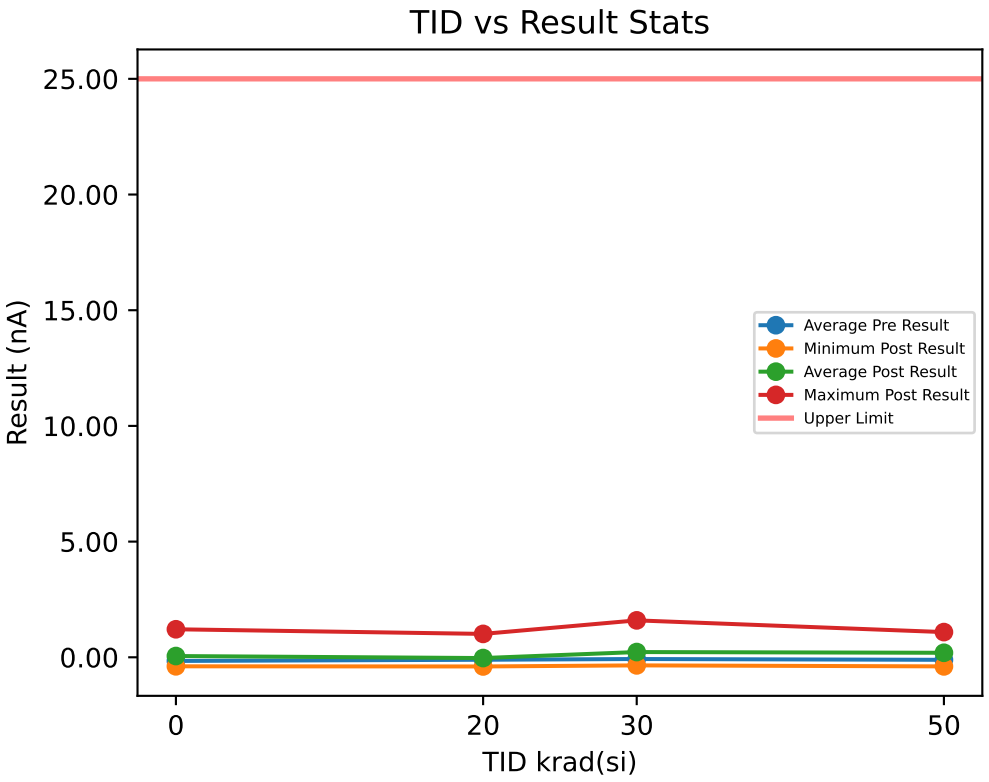
Test Results (Upper Limit = 25.0 (nA))

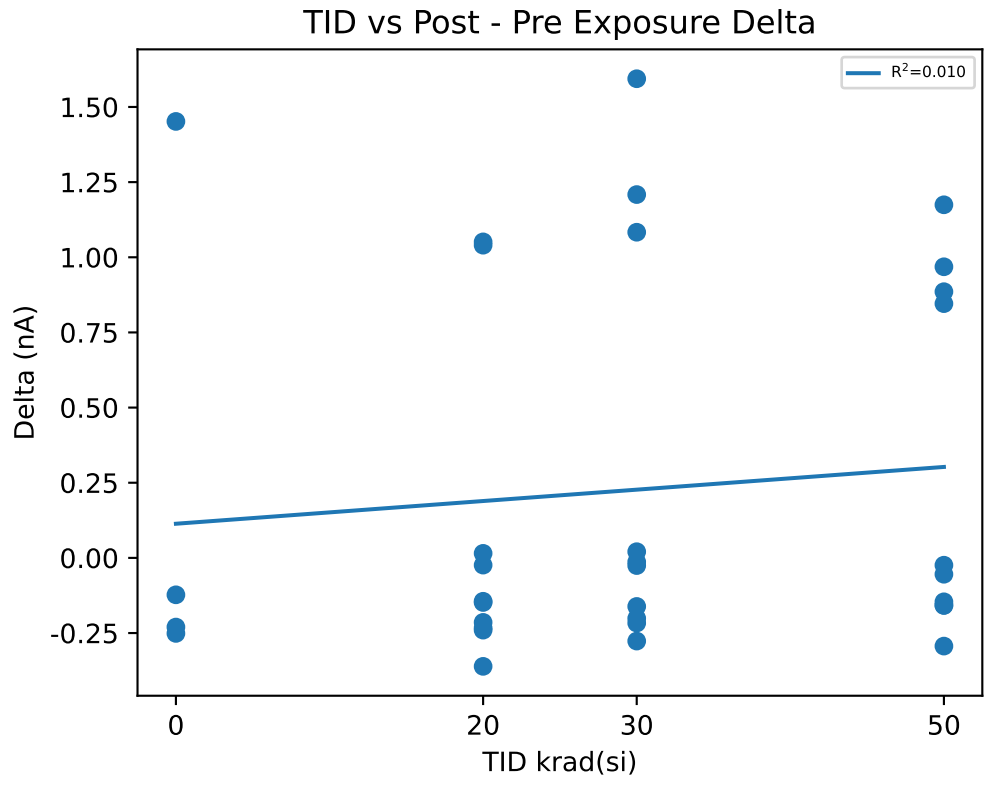
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	0.0651	1.0391	0.974
2	20	Unbiased	-0.1619	1.0734	1.2353
3	50	Biased	-0.0417	0.7517	0.7934
4	30	Unbiased	-0.0196	-0.1519	-0.1323
5	50	Unbiased	0.0245	-0.1299	-0.1544
6	30	Biased	-0.0589	-0.2016	-0.1427
7	50	Biased	-0.1792	1.1453	1.3245
8	30	Unbiased	-0.0196	-0.29	-0.2704
9	20	Unbiased	-0.0255	-0.1582	-0.1327
10	50	Biased	-0.0995	-0.2235	-0.124
11	30	Biased	-0.2355	-0.2859	-0.0504
12	0	Correlation	-0.0789	-0.1642	-0.0853
13	0	Correlation	-0.0879	0.986	1.0739
14	50	Unbiased	-0.1026	-0.2424	-0.1398
15	20	Biased	-0.1074	-0.2828	-0.1754
16	20	Unbiased	-0.0508	-0.3648	-0.314
17	20	Biased	-0.1941	-0.3617	-0.1676
18	20	Unbiased	-0.087	-0.3836	-0.2966
19	20	Biased	-0.023	1.1234	1.1464
20	50	Unbiased	-0.0196	-0.1519	-0.1323
21	0	Correlation	0.0027	-0.3555	-0.3582
22	50	Unbiased	-0.0964	-0.2362	-0.1398
23	0	Correlation	-0.0949	-0.3742	-0.2793
24	20	Biased	0.0304	-0.3648	-0.3952
26	50	Biased	-0.0808	-0.3773	-0.2965
27	30	Unbiased	-0.2167	-0.1332	0.0835
28	30	Biased	0.0023	0.811	0.8087
29	30	Unbiased	-0.0786	1.0859	1.1645
30	20	Biased	-0.1089	-0.2141	-0.1052
31	30	Unbiased	-0.2511	-0.3586	-0.1075
33	30	Biased	-0.0629	-0.1642	-0.1013
34	50	Unbiased	0.0441	1.1828	1.1387
35	20	Unbiased	-0.1261	-0.2672	-0.1411
41	30	Biased	0.0988	1.4712	1.3724

Test Statistics (nA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.0949	-0.06475	0.0027	0.045441	-0.3742	0.023025	0.986	0.64896	-0.3582	0.087775	1.0739	0.66734
20	-0.1941	-0.08543	0.0304	0.068679	-0.3836	-0.02004	1.1234	0.5941	-0.3952	0.06539	1.2353	0.60071
30	-0.2511	-0.08418	0.0988	0.11487	-0.3586	0.17827	1.4712	0.67383	-0.2704	0.26245	1.3724	0.60983
50	-0.1792	-0.04861	0.0651	0.0772	-0.3773	0.27577	1.1828	0.6618	-0.2965	0.32438	1.3245	0.64641

Device Test: 19.22 CURRENT|EA//12/12/0/0/5/1MHz//@EA_IB





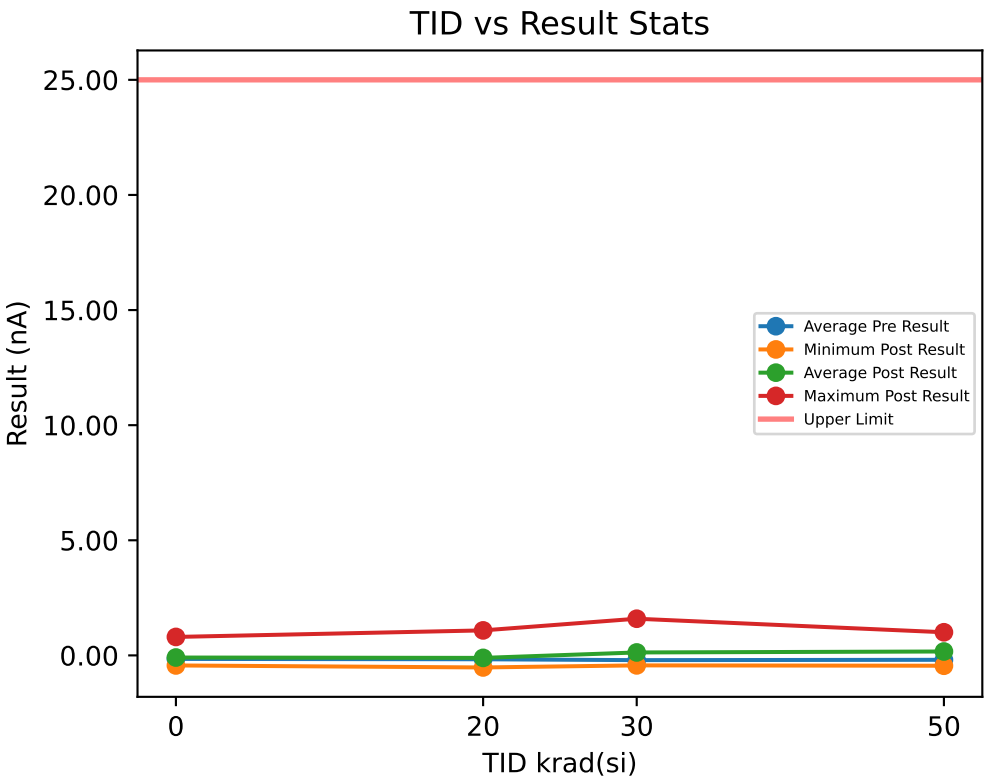
Test Results (Upper Limit = 25.0 (nA))

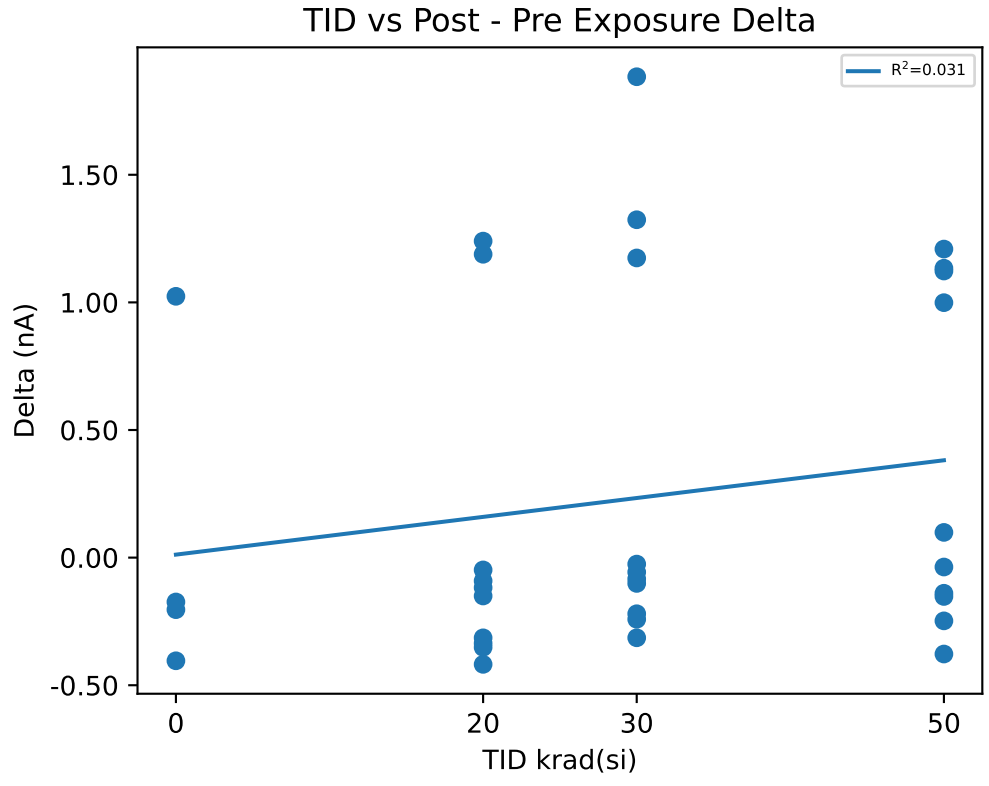
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	-0.1566	0.6892	0.8458
2	20	Unbiased	-0.0402	1.011	1.0512
3	50	Biased	-0.0855	1.0891	1.1746
4	30	Unbiased	-0.0133	-0.23	-0.2167
5	50	Unbiased	-0.1504	-0.2048	-0.0544
6	30	Biased	-0.0433	-0.2048	-0.1615
7	50	Biased	-0.1105	0.8579	0.9684
8	30	Unbiased	-0.032	-0.3087	-0.2767
9	20	Unbiased	-0.0473	-0.1956	-0.1483
10	50	Biased	-0.0995	-0.2578	-0.1583
11	30	Biased	-0.2105	-0.236	-0.0255
12	0	Correlation	-0.1257	-0.2485	-0.1228
13	0	Correlation	-0.241	1.2109	1.4519
14	50	Unbiased	-0.0683	-0.2144	-0.1461
15	20	Biased	-0.0542	-0.1985	-0.1443
16	20	Unbiased	-0.0913	-0.3243	-0.233
17	20	Biased	-0.3284	-0.3524	-0.024
18	20	Unbiased	-0.137	-0.3773	-0.2403
19	20	Biased	-0.0542	0.986	1.0402
20	50	Unbiased	-0.1101	-0.2674	-0.1573
21	0	Correlation	-0.1254	-0.3555	-0.2301
22	50	Unbiased	-0.1276	-0.1519	-0.0243
23	0	Correlation	-0.1386	-0.3898	-0.2512
24	20	Biased	-0.0352	-0.396	-0.3608
26	50	Biased	-0.0995	-0.3929	-0.2934
27	30	Unbiased	-0.1761	-0.1894	-0.0133
28	30	Biased	-0.0539	1.1547	1.2086
29	30	Unbiased	0.1214	1.2047	1.0833
30	20	Biased	-0.0496	-0.2641	-0.2145
31	30	Unbiased	-0.148	-0.3492	-0.2012
33	30	Biased	-0.191	-0.1704	0.0206
34	50	Unbiased	-0.0839	0.8016	0.8855
35	20	Unbiased	-0.2292	-0.2141	0.0151
41	30	Biased	0.002	1.5959	1.5939

Test Statistics (nA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.241	-0.15768	-0.1254	0.05589	-0.3898	0.054275	1.2109	0.77343	-0.2512	0.21195	1.4519	0.82854
20	-0.3284	-0.10666	-0.0352	0.098403	-0.396	-0.03253	1.011	0.54828	-0.3608	0.07413	1.0512	0.52323
30	-0.2105	-0.07447	0.1214	0.10487	-0.3492	0.22668	1.5959	0.76379	-0.2767	0.30115	1.5939	0.70389
50	-0.1566	-0.10919	-0.0683	0.028574	-0.3929	0.19486	1.0891	0.58341	-0.2934	0.30405	1.1746	0.58246

Device Test: 19.23 CURRENT|EA//14/14/0/0/5/100kHz//@EA_IB





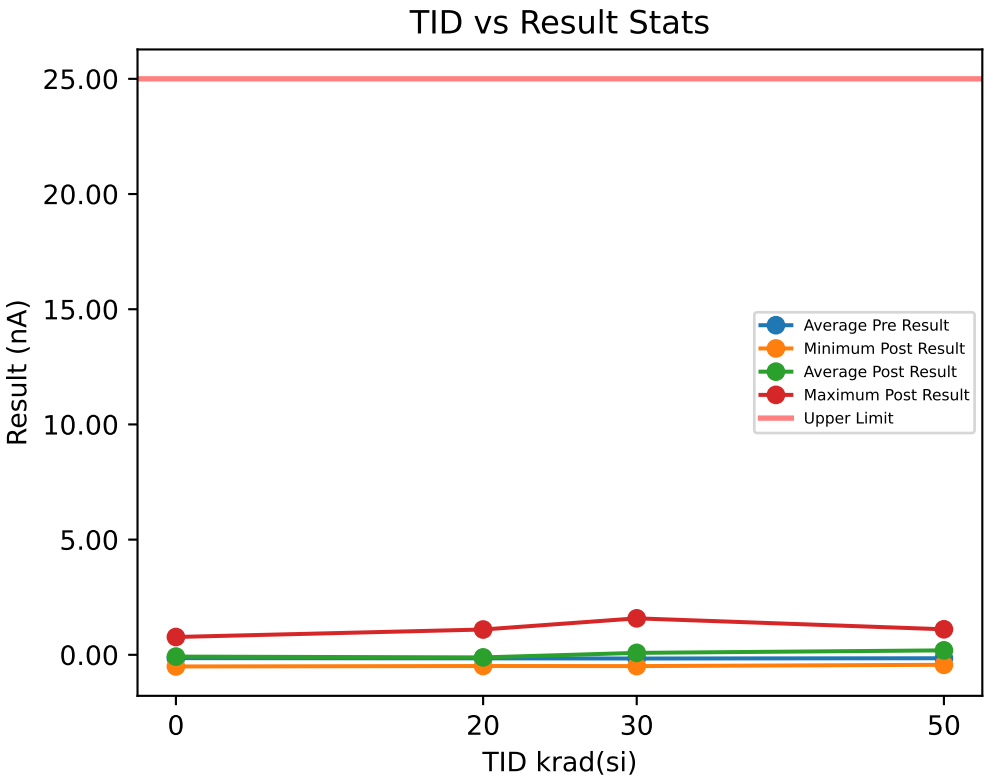
Test Results (Upper Limit = 25.0 (nA))

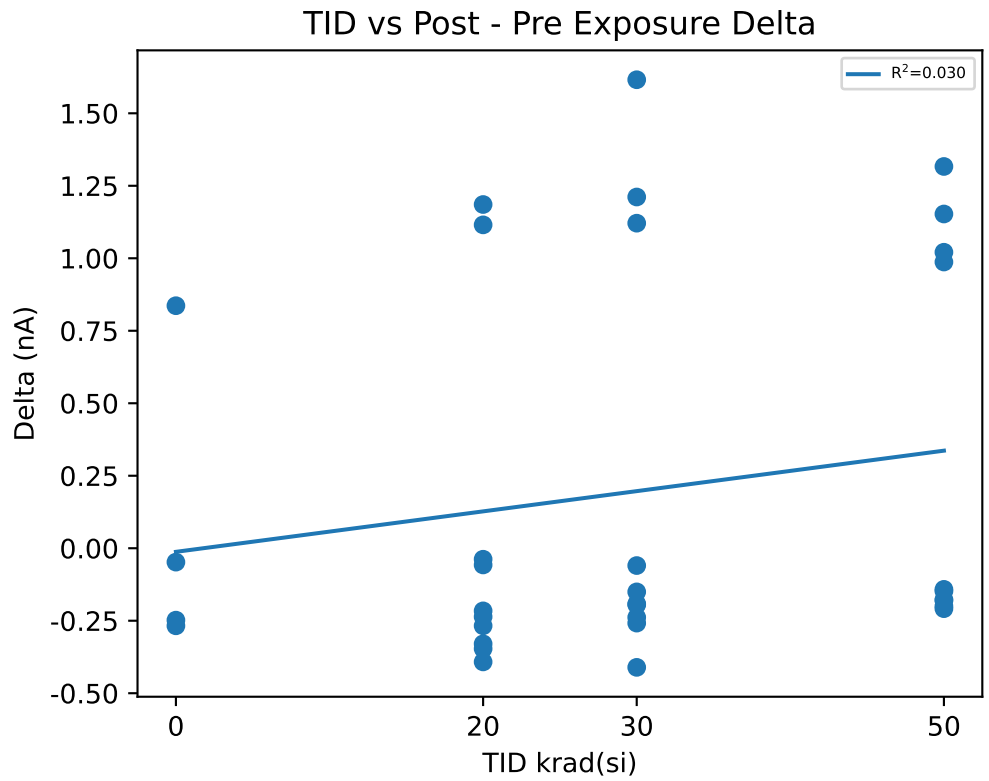
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	-0.2816	0.7173	0.9989
2	20	Unbiased	-0.1994	0.9891	1.1885
3	50	Biased	-0.1417	0.9922	1.1339
4	30	Unbiased	-0.0633	-0.3048	-0.2415
5	50	Unbiased	-0.3753	-0.2765	0.0988
6	30	Biased	-0.215	-0.2984	-0.0834
7	50	Biased	-0.2542	0.9547	1.2089
8	30	Unbiased	-0.1194	-0.4335	-0.3141
9	20	Unbiased	-0.2816	-0.3298	-0.0482
10	50	Biased	-0.1838	-0.3234	-0.1396
11	30	Biased	-0.2761	-0.3015	-0.0254
12	0	Correlation	-0.0945	-0.2984	-0.2039
13	0	Correlation	-0.2222	0.8016	1.0238
14	50	Unbiased	-0.24	-0.2768	-0.0368
15	20	Biased	-0.2011	-0.3514	-0.1503
16	20	Unbiased	-0.0882	-0.4397	-0.3515
17	20	Biased	-0.1598	-0.4741	-0.3143
18	20	Unbiased	-0.1058	-0.524	-0.4182
19	20	Biased	-0.1542	1.0859	1.2401
20	50	Unbiased	-0.0851	-0.3329	-0.2478
21	0	Correlation	-0.2628	-0.4366	-0.1738
22	50	Unbiased	-0.1651	-0.3173	-0.1522
23	0	Correlation	-0.0324	-0.4366	-0.4042
24	20	Biased	-0.1038	-0.4397	-0.3359
26	50	Biased	-0.0714	-0.4491	-0.3777
27	30	Unbiased	-0.1949	-0.2518	-0.0569
28	30	Biased	-0.135	1.0391	1.1741
29	30	Unbiased	-0.2941	1.0297	1.3238
30	20	Biased	-0.2119	-0.3296	-0.1177
31	30	Unbiased	-0.2136	-0.4335	-0.2199
33	30	Biased	-0.2597	-0.3608	-0.1011
34	50	Unbiased	-0.1182	1.0047	1.1229
35	20	Unbiased	-0.1792	-0.2703	-0.0911
41	30	Biased	-0.2913	1.5928	1.8841

Test Statistics (nA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.2628	-0.15297	-0.0324	0.10772	-0.4366	-0.0925	0.8016	0.59962	-0.4042	0.060475	1.0238	0.65031
20	-0.2816	-0.1685	-0.0882	0.059304	-0.524	-0.10836	1.0859	0.60919	-0.4182	0.06014	1.2401	0.62105
30	-0.2941	-0.20624	-0.0633	0.078882	-0.4335	0.12773	1.5928	0.77144	-0.3141	0.33397	1.8841	0.80221
50	-0.3753	-0.19164	-0.0714	0.095765	-0.4491	0.16929	1.0047	0.65014	-0.3777	0.36093	1.2089	0.66341

Device Test: 19.24 CURRENT|EA//14/14/0/0/5/1MHz//@EA_IB





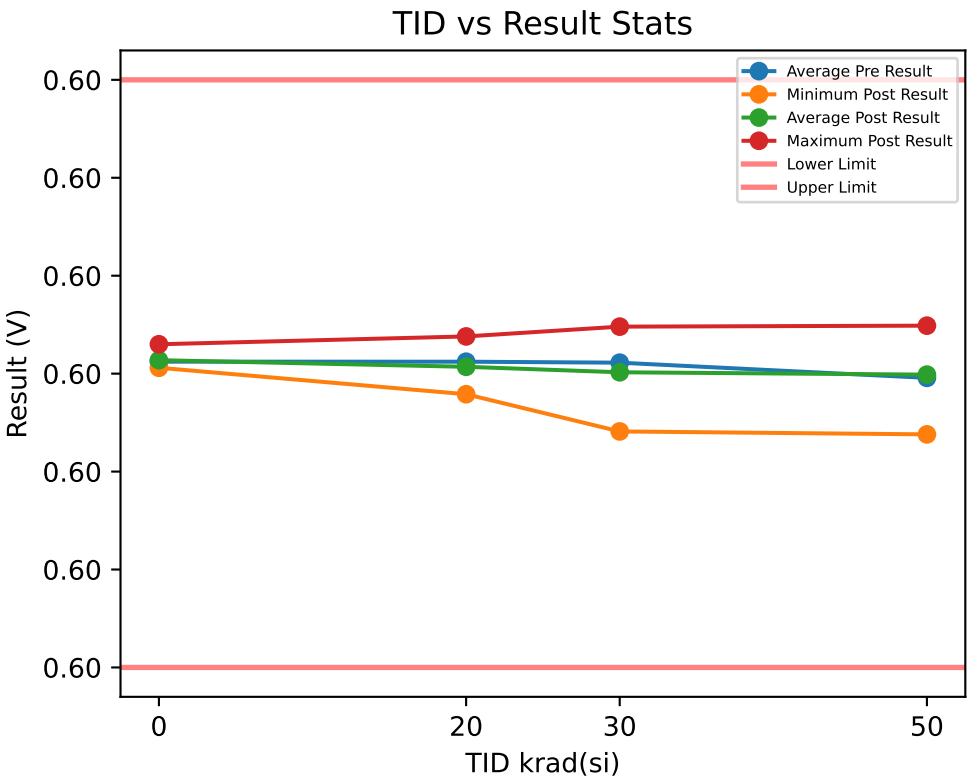
Test Results (Upper Limit = 25.0 (nA))

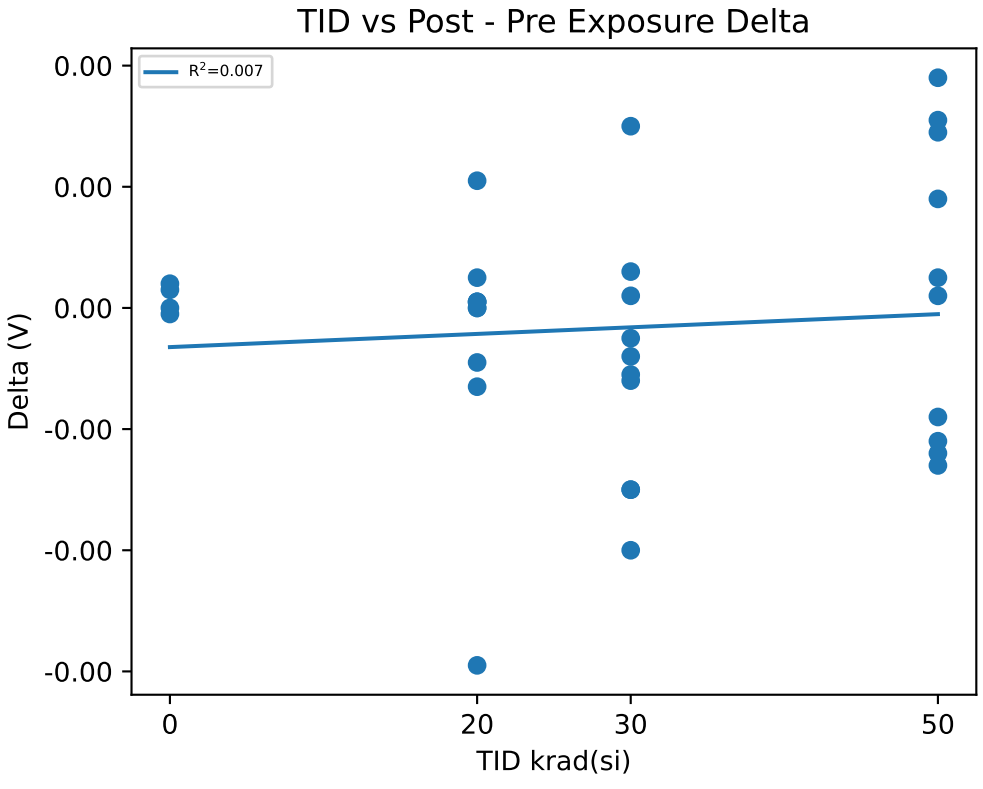
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	-0.0754	0.9454	1.0208
2	20	Unbiased	-0.087	1.0984	1.1854
3	50	Biased	-0.1074	1.0453	1.1527
4	30	Unbiased	-0.0945	-0.3329	-0.2384
5	50	Unbiased	-0.1441	-0.2859	-0.1418
6	30	Biased	-0.1089	-0.3671	-0.2582
7	50	Biased	-0.123	0.8641	0.9871
8	30	Unbiased	-0.0789	-0.4897	-0.4108
9	20	Unbiased	-0.3003	-0.3579	-0.0576
10	50	Biased	-0.1463	-0.3265	-0.1802
11	30	Biased	-0.2855	-0.3452	-0.0597
12	0	Correlation	-0.1225	-0.1704	-0.0479
13	0	Correlation	-0.0629	0.7735	0.8364
14	50	Unbiased	-0.1588	-0.3361	-0.1773
15	20	Biased	-0.1292	-0.3452	-0.216
16	20	Unbiased	-0.0757	-0.4054	-0.3297
17	20	Biased	-0.1754	-0.4428	-0.2674
18	20	Unbiased	-0.1401	-0.4865	-0.3464
19	20	Biased	-0.1636	0.9516	1.1152
20	50	Unbiased	-0.1818	-0.3298	-0.148
21	0	Correlation	-0.1379	-0.4054	-0.2675
22	50	Unbiased	-0.112	-0.3204	-0.2084
23	0	Correlation	-0.2573	-0.5053	-0.248
24	20	Biased	-0.0633	-0.4553	-0.392
26	50	Biased	-0.2337	-0.4335	-0.1998
27	30	Unbiased	-0.1824	-0.3329	-0.1505
28	30	Biased	-0.1163	1.0047	1.121
29	30	Unbiased	-0.3222	0.8891	1.2113
30	20	Biased	-0.1651	-0.4014	-0.2363
31	30	Unbiased	-0.2636	-0.4585	-0.1949
33	30	Biased	-0.1192	-0.3109	-0.1917
34	50	Unbiased	-0.2088	1.1078	1.3166
35	20	Unbiased	-0.2386	-0.2765	-0.0379
41	30	Biased	-0.0323	1.5834	1.6157

Test Statistics (nA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.2573	-0.14515	-0.0629	0.081462	-0.5053	-0.0769	0.7735	0.58406	-0.2675	0.06825	0.8364	0.52163
20	-0.3003	-0.15383	-0.0633	0.073702	-0.4865	-0.1121	1.0984	0.60329	-0.392	0.04173	1.1854	0.59559
30	-0.3222	-0.16038	-0.0323	0.098123	-0.4897	0.084	1.5834	0.7644	-0.4108	0.24438	1.6157	0.75501
50	-0.2337	-0.14913	-0.0754	0.048472	-0.4335	0.19304	1.1078	0.69028	-0.2084	0.34217	1.3166	0.6747

Device Test: 19.25 VOLTAGE|VREF//4.5/4.5/0/0/4.5/100kHz//@VREF_25C





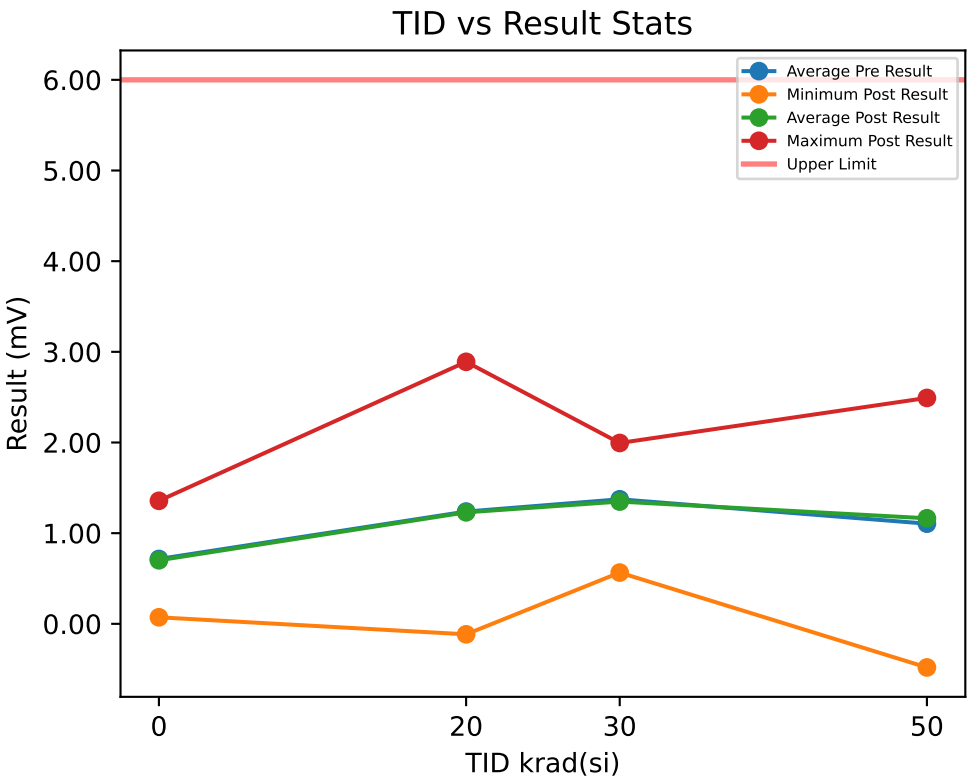
Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

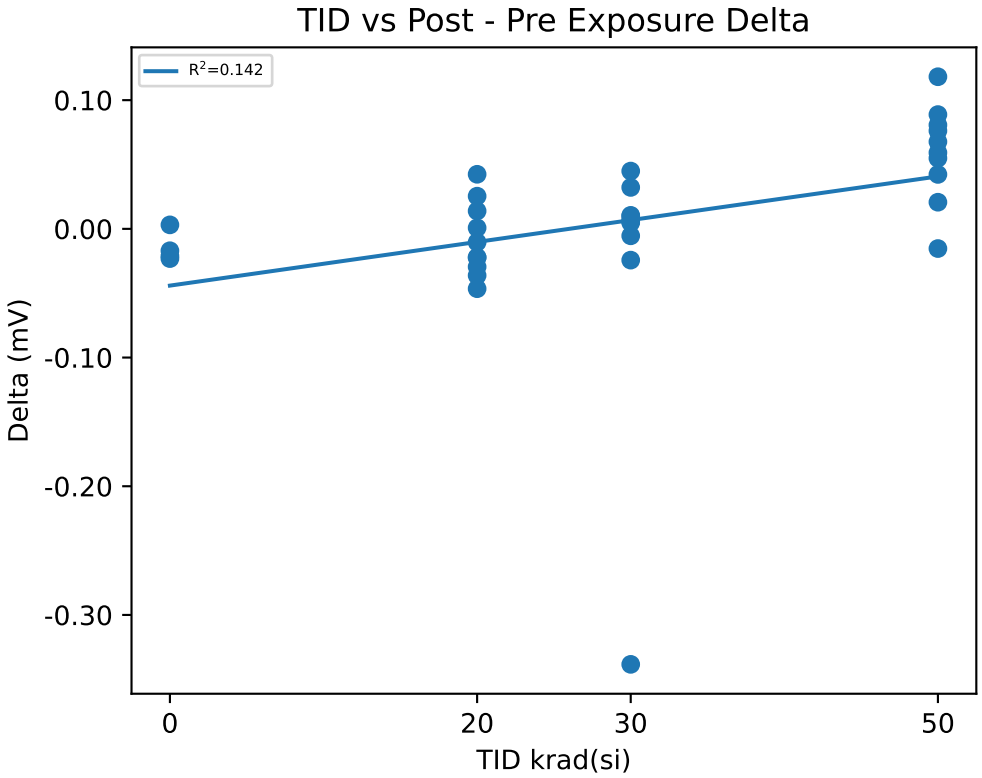
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	0.60004	0.60009	5e-05
2	20	Unbiased	0.60034	0.60035	1e-05
3	50	Biased	0.59964	0.59938	-0.00026
4	30	Unbiased	0.59985	0.59973	-0.00012
5	50	Unbiased	0.6002	0.60022	2e-05
6	30	Biased	0.59982	0.59952	-0.0003
7	50	Biased	0.59987	0.59963	-0.00024
8	30	Unbiased	0.59981	0.59941	-0.0004
9	20	Unbiased	0.59978	0.59999	0.00021
10	50	Biased	0.59963	0.59941	-0.00022
11	30	Biased	0.60038	0.60027	-0.00011
12	0	Correlation	0.60008	0.60008	0
13	0	Correlation	0.60026	0.6003	4e-05
14	50	Unbiased	0.59988	0.5997	-0.00018
15	20	Biased	0.59999	0.59986	-0.00013
16	20	Unbiased	0.60006	0.60006	0
17	20	Biased	0.59992	0.59997	5e-05
18	20	Unbiased	0.6004	0.59981	-0.00059
19	20	Biased	0.60028	0.60028	0
20	50	Unbiased	0.60031	0.60049	0.00018
21	0	Correlation	0.60008	0.60011	3e-05
22	50	Unbiased	0.59999	0.60037	0.00038
23	0	Correlation	0.60007	0.60006	-1e-05
24	20	Biased	0.60037	0.60038	1e-05
26	50	Biased	0.60006	0.60035	0.00029
27	30	Unbiased	0.59999	0.60005	6e-05
28	30	Biased	0.60033	0.60003	-0.0003
29	30	Unbiased	0.60039	0.60031	-8e-05
30	20	Biased	0.59978	0.59979	1e-05
31	30	Unbiased	0.60035	0.60037	2e-05
33	30	Biased	0.60002	0.59997	-5e-05
34	50	Unbiased	0.59995	0.60026	0.00031
35	20	Unbiased	0.6003	0.60021	-9e-05
41	30	Biased	0.60018	0.60048	0.0003

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.60007	0.60012	0.60026	9.1788e-05	0.60006	0.60014	0.6003	0.00011026	-1e-05	1.5e-05	4e-05	2.3805e-05
20	0.59978	0.60012	0.6004	0.00024471	0.59979	0.60007	0.60038	0.00022231	-0.00059	-5.2e-05	0.00021	0.00020896
30	0.59981	0.60011	0.60039	0.00024184	0.59941	0.60001	0.60048	0.00036363	-0.0004	-9.8e-05	0.0003	0.00020368
50	0.59963	0.59996	0.60031	0.00021685	0.59938	0.59999	0.60049	0.00041926	-0.00026	3.3e-05	0.00038	0.00024833

Device Test: 19.27 VOLTAGE|OFFSET//4.5/4.5/0/0/4.5/100kHz//@EA_OS





Test Results (Upper Limit = 6.0 (mV))

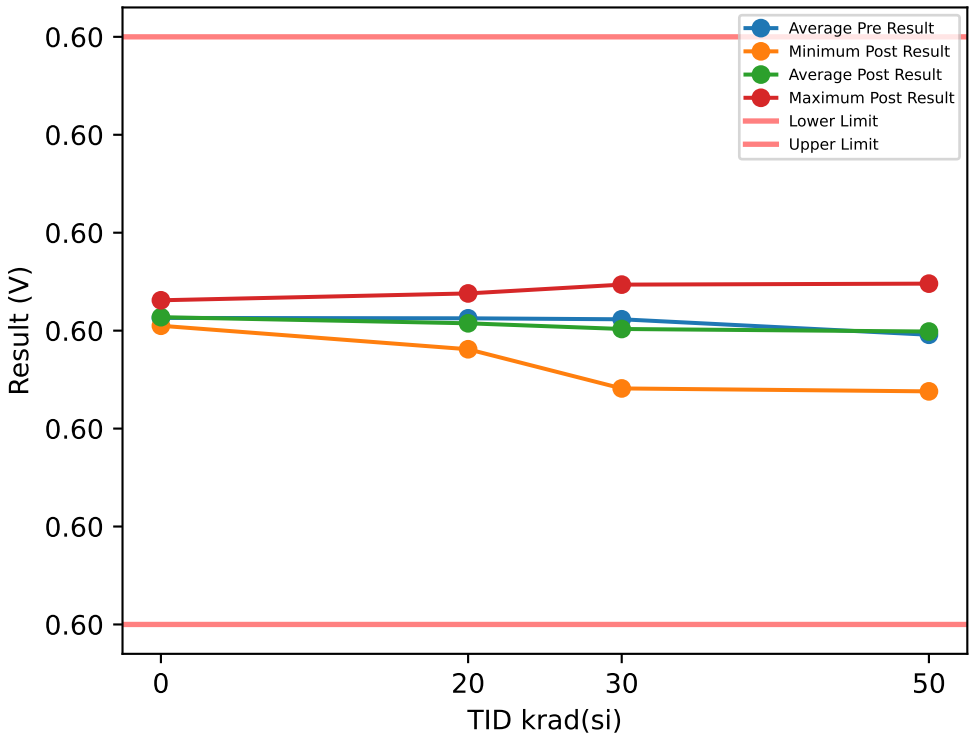
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	1.5843	1.569	-0.0153
2	20	Unbiased	0.7163	0.7302	0.0139
3	50	Biased	-0.5403	-0.4811	0.0592
4	30	Unbiased	1.2659	1.2726	0.0067
5	50	Unbiased	2.4709	2.4916	0.0207
6	30	Biased	1.3342	1.3447	0.0105
7	50	Biased	1.0135	1.0684	0.0549
8	30	Unbiased	1.7075	1.7173	0.0098
9	20	Unbiased	1.9801	2.0225	0.0424
10	50	Biased	1.7576	1.8338	0.0762
11	30	Biased	1.7219	1.7541	0.0322
12	0	Correlation	0.7736	0.7505	-0.0231
13	0	Correlation	0.069	0.0721	0.0031
14	50	Unbiased	1.8458	1.9265	0.0807
15	20	Biased	1.9601	1.938	-0.0221
16	20	Unbiased	0.115	0.0685	-0.0465
17	20	Biased	1.5736	1.5441	-0.0295
18	20	Unbiased	0.3593	0.3489	-0.0104
19	20	Biased	1.6738	1.6746	0.0008
20	50	Unbiased	0.2885	0.3308	0.0423
21	0	Correlation	1.378	1.3569	-0.0211
22	50	Unbiased	-0.064	0.0248	0.0888
23	0	Correlation	0.6415	0.6245	-0.017
24	20	Biased	1.2338	1.1976	-0.0362
26	50	Biased	1.9232	1.9909	0.0677
27	30	Unbiased	1.4767	1.5216	0.0449
28	30	Biased	0.5708	0.5654	-0.0054
29	30	Unbiased	0.9571	0.9328	-0.0243
30	20	Biased	2.9122	2.8899	-0.0223
31	30	Unbiased	1.989	1.9947	0.0057
33	30	Biased	0.7407	0.7455	0.0048
34	50	Unbiased	0.7691	0.8873	0.1182
35	20	Unbiased	-0.141	-0.1156	0.0254
41	30	Biased	1.9737	1.6353	-0.3384

Test Statistics (mV)

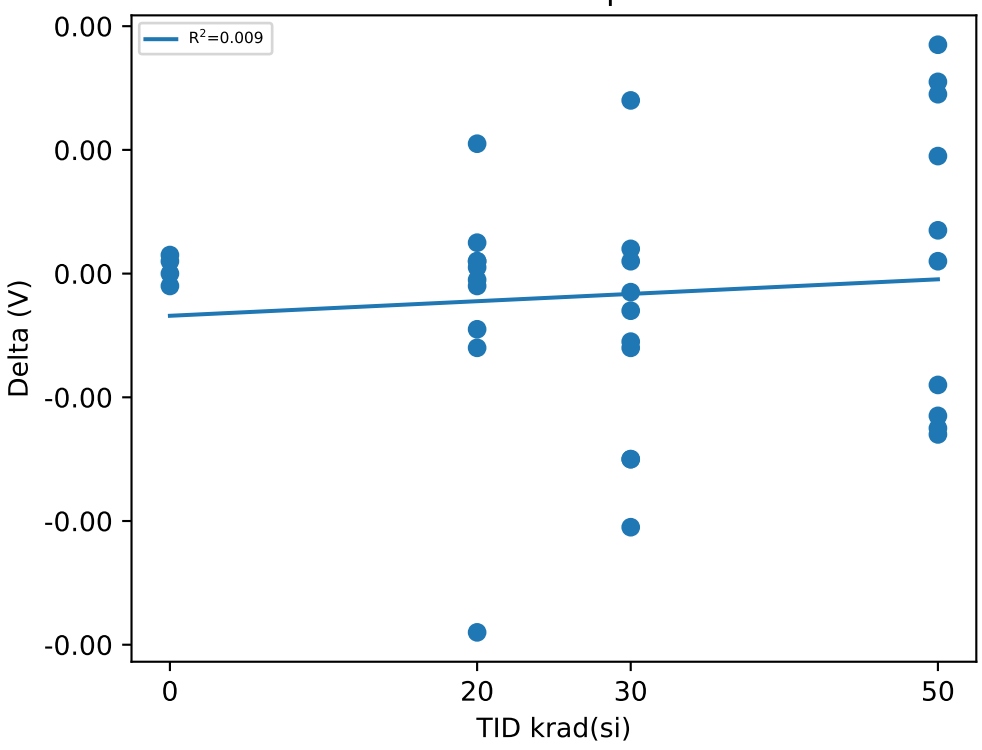
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.069	0.71552	1.378	0.53719	0.0721	0.701	1.3569	0.52726	-0.0231	-0.014525	0.0031	0.012021
20	-0.141	1.2383	2.9122	0.96521	-0.1156	1.2299	2.8899	0.96424	-0.0465	-0.00845	0.0424	0.028596
30	0.5708	1.3738	1.989	0.49598	0.5654	1.3484	1.9947	0.46972	-0.3384	-0.02535	0.0449	0.11159
50	-0.5403	1.1049	2.4709	0.97758	-0.4811	1.1642	2.4916	0.96749	-0.0153	0.05934	0.1182	0.037293

Device Test: 19.28 VOLTAGE|VREF//5/5/0/0/5/100kHz//@VREF_25C

TID vs Result Stats



TID vs Post - Pre Exposure Delta



Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

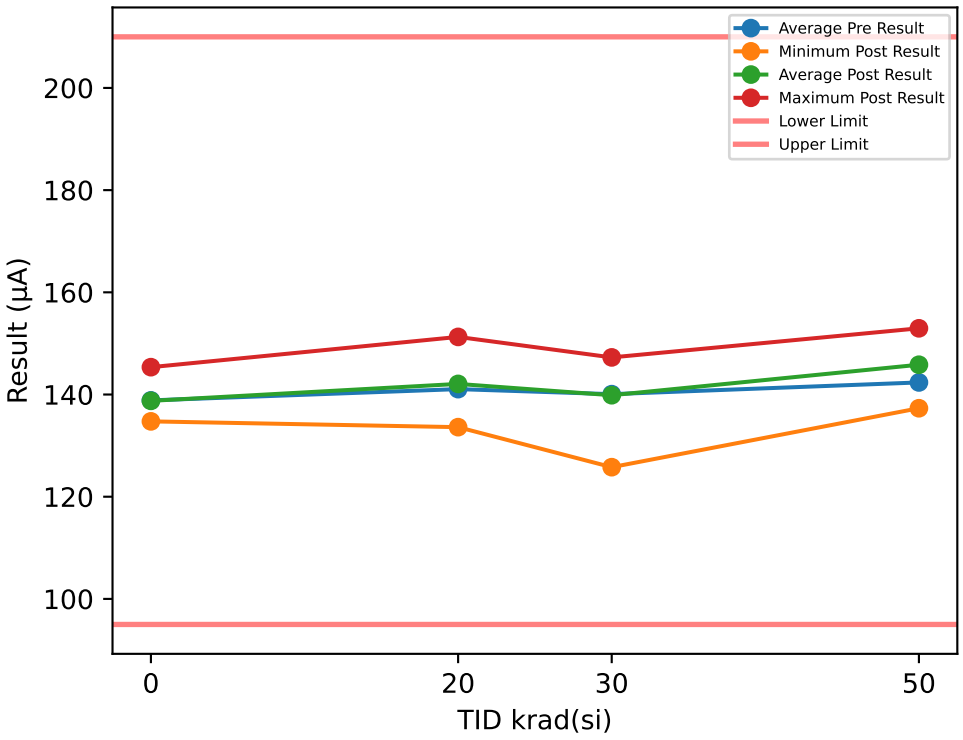
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	0.60003	0.6001	7e-05
2	20	Unbiased	0.60033	0.60035	2e-05
3	50	Biased	0.59964	0.59938	-0.00026
4	30	Unbiased	0.59984	0.59972	-0.00012
5	50	Unbiased	0.60021	0.60023	2e-05
6	30	Biased	0.59982	0.59952	-0.0003
7	50	Biased	0.59989	0.59964	-0.00025
8	30	Unbiased	0.59982	0.59941	-0.00041
9	20	Unbiased	0.59978	0.59999	0.00021
10	50	Biased	0.59963	0.5994	-0.00023
11	30	Biased	0.6004	0.60029	-0.00011
12	0	Correlation	0.60008	0.60008	0
13	0	Correlation	0.60028	0.60031	3e-05
14	50	Unbiased	0.59987	0.59969	-0.00018
15	20	Biased	0.59997	0.59985	-0.00012
16	20	Unbiased	0.60007	0.60006	-1e-05
17	20	Biased	0.59993	0.59998	5e-05
18	20	Unbiased	0.6004	0.59982	-0.00058
19	20	Biased	0.60029	0.60027	-2e-05
20	50	Unbiased	0.60029	0.60048	0.00019
21	0	Correlation	0.60009	0.60011	2e-05
22	50	Unbiased	0.6	0.60037	0.00037
23	0	Correlation	0.60007	0.60005	-2e-05
24	20	Biased	0.60037	0.60038	1e-05
26	50	Biased	0.60006	0.60035	0.00029
27	30	Unbiased	0.6	0.60004	4e-05
28	30	Biased	0.60034	0.60004	-0.0003
29	30	Unbiased	0.60038	0.60032	-6e-05
30	20	Biased	0.59979	0.59981	2e-05
31	30	Unbiased	0.60035	0.60037	2e-05
33	30	Biased	0.60002	0.59999	-3e-05
34	50	Unbiased	0.59996	0.60027	0.00031
35	20	Unbiased	0.60033	0.60024	-9e-05
41	30	Biased	0.60019	0.60047	0.00028

Test Statistics (V)

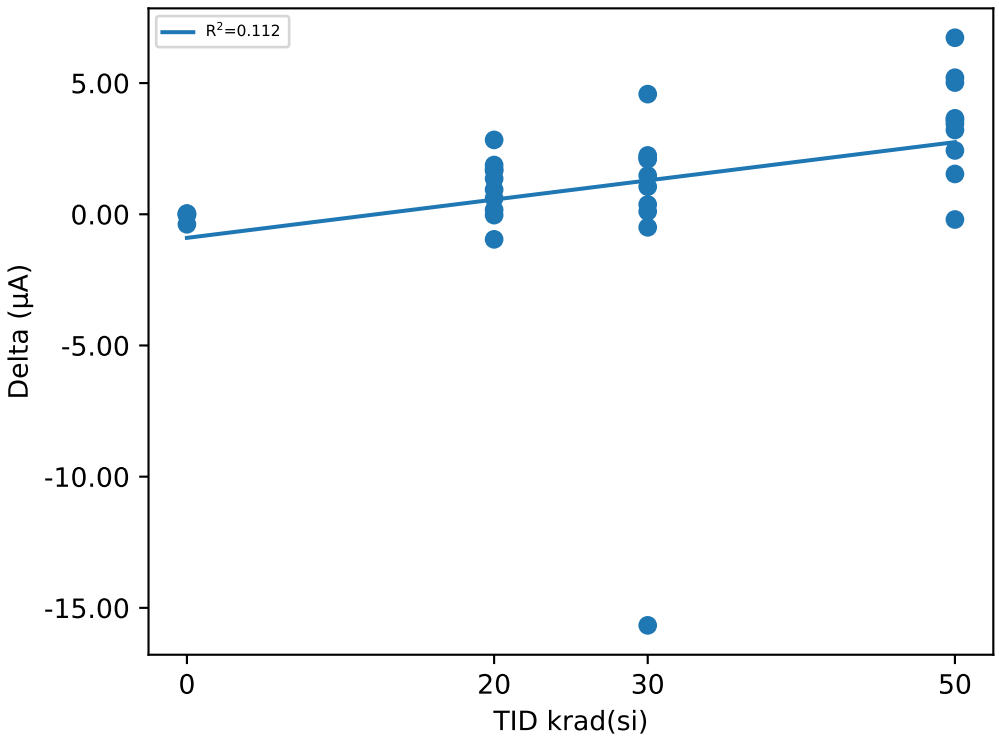
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.60007	0.60013	0.60028	0.00010033	0.60005	0.60014	0.60031	0.00011758	-2e-05	7.5e-06	3e-05	2.2174e-05
20	0.59978	0.60013	0.6004	0.00024568	0.59981	0.60008	0.60038	0.00022016	-0.00058	-5.1e-05	0.00021	0.00020572
30	0.59982	0.60012	0.6004	0.00024378	0.59941	0.60002	0.60047	0.00036539	-0.00041	-9.9e-05	0.00028	0.00020041
50	0.59963	0.59996	0.60029	0.000214	0.59938	0.59999	0.60048	0.00042096	-0.00026	3.3e-05	0.00037	0.00025011

Device Test: 19.3 CURRENT|EA_SINK//4.5/4.5/0/0/4.5/500kHz//@EA_I_SINK

TID vs Result Stats



TID vs Post - Pre Exposure Delta



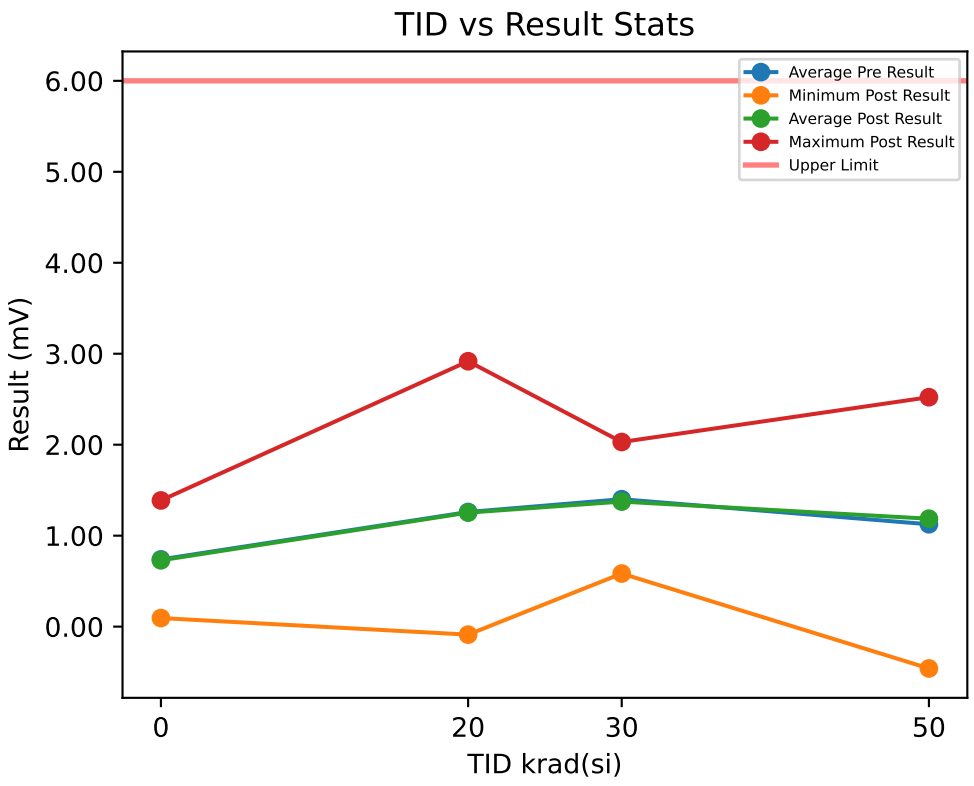
Test Results (Lower Limit = 95.0, Upper Limit = 210.0 (µA))

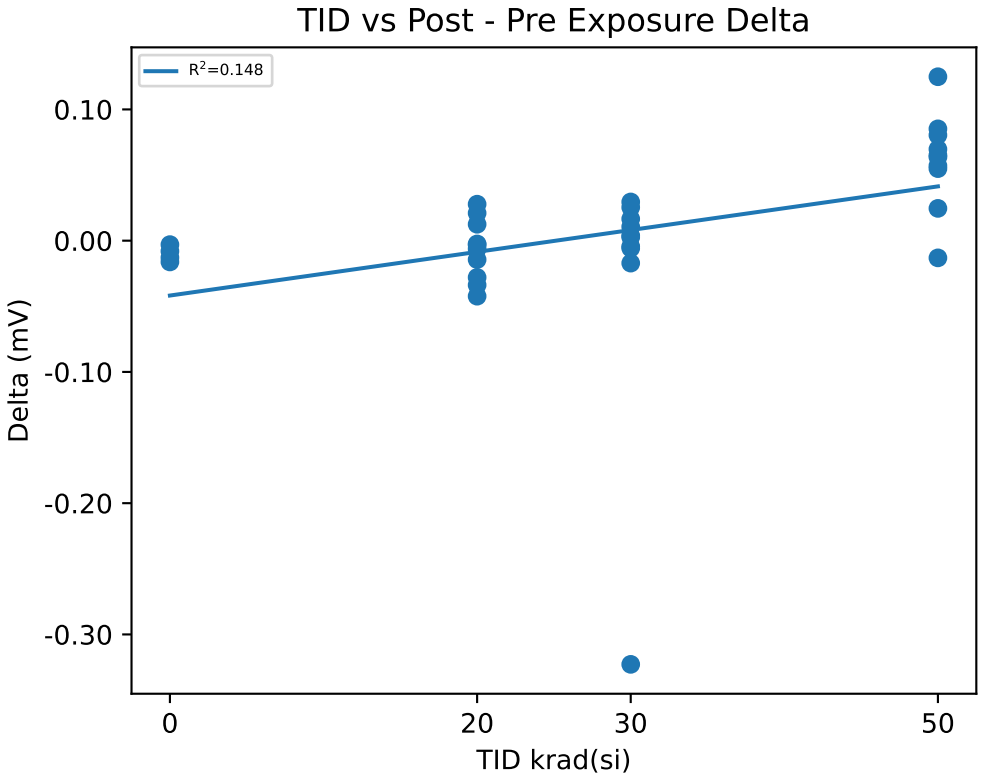
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	140.24	141.77	1.5364
2	20	Unbiased	145.84	146.46	0.6123
3	50	Biased	137.51	137.31	-0.199
4	30	Unbiased	145.02	147.26	2.2433
5	50	Unbiased	140.33	145.35	5.0201
6	30	Biased	138.4	137.9	-0.4966
7	50	Biased	149.51	152.96	3.4483
8	30	Unbiased	142.16	143.64	1.4763
9	20	Unbiased	134.68	136.4	1.7176
10	50	Biased	144.9	148.56	3.6574
11	30	Biased	137.04	137.15	0.1083
12	0	Correlation	145.33	145.35	0.0178
13	0	Correlation	135.56	135.18	-0.3808
14	50	Unbiased	146.47	149.68	3.2114
15	20	Biased	144.14	143.18	-0.9552
16	20	Unbiased	132.67	133.61	0.9409
17	20	Biased	143.79	145.15	1.3586
18	20	Unbiased	149.61	151.27	1.6626
19	20	Biased	144.3	146.17	1.8762
20	50	Unbiased	142	145.6	3.595
21	0	Correlation	139.8	139.77	-0.0262
22	50	Unbiased	142.67	149.4	6.7282
23	0	Correlation	134.72	134.74	0.0267
24	20	Biased	141.25	141.22	-0.0322
26	50	Biased	137.9	143.1	5.205
27	30	Unbiased	145.65	146.7	1.0517
28	30	Biased	144.83	146.99	2.1573
29	30	Unbiased	133.77	135.87	2.1005
30	20	Biased	138.24	141.08	2.8346
31	30	Unbiased	133.4	133.77	0.3715
33	30	Biased	138.98	143.56	4.5793
34	50	Unbiased	142.11	144.54	2.4329
35	20	Unbiased	136.04	136.21	0.1704
41	30	Biased	141.45	125.78	-15.667

Test Statistics (µA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	134.72	138.85	145.33	4.8601	134.74	138.76	145.35	4.9479	-0.3808	-0.090625	0.0267	0.19483
20	132.67	141.06	149.61	5.4535	133.61	142.07	151.27	5.49	-0.9552	1.0186	2.8346	1.1027
30	133.4	140.07	145.65	4.4958	125.78	139.86	147.26	7.0143	-15.667	-0.20753	4.5793	5.6152
50	137.51	142.36	149.51	3.7531	137.31	145.83	152.96	4.5238	-0.199	3.4636	6.7282	1.9557

Device Test: 19.30 VOLTAGE|OFFSET//5/5/0/0/5/100kHz//@EA_OS





Test Results (Upper Limit = 6.0 (mV))

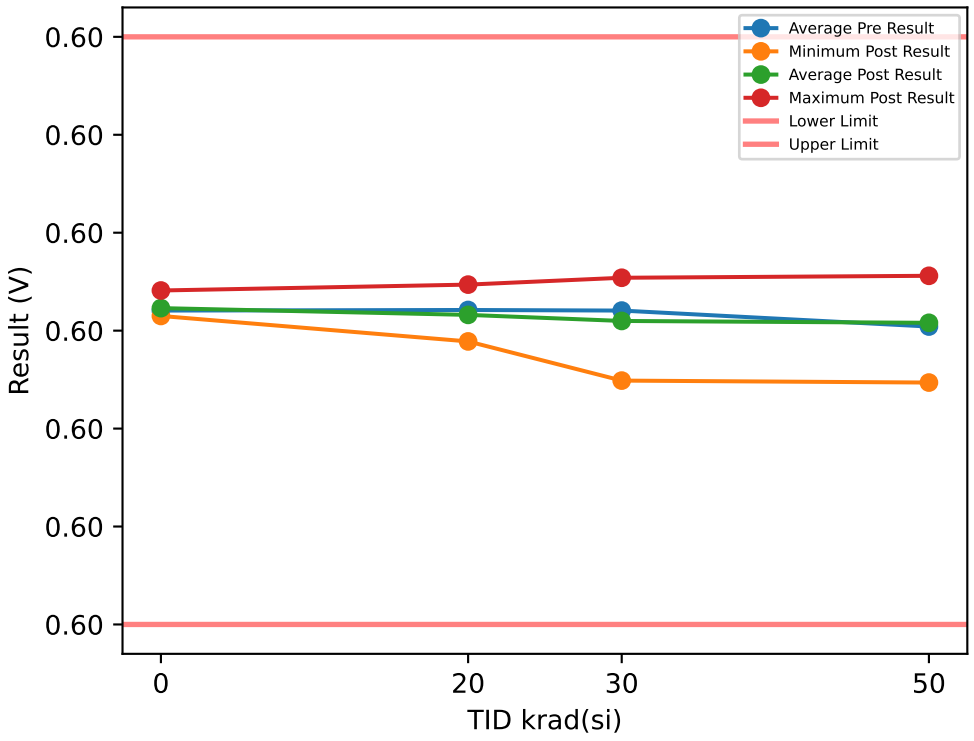
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	1.6143	1.6012	-0.0131
2	20	Unbiased	0.7261	0.7386	0.0125
3	50	Biased	-0.5235	-0.4598	0.0637
4	30	Unbiased	1.2891	1.2918	0.0027
5	50	Unbiased	2.4975	2.5221	0.0246
6	30	Biased	1.3571	1.3737	0.0166
7	50	Biased	1.0346	1.0917	0.0571
8	30	Unbiased	1.7384	1.7327	-0.0057
9	20	Unbiased	2.0077	2.0355	0.0278
10	50	Biased	1.7821	1.8518	0.0697
11	30	Biased	1.7552	1.7847	0.0295
12	0	Correlation	0.7957	0.7828	-0.0129
13	0	Correlation	0.0972	0.0942	-0.003
14	50	Unbiased	1.8685	1.9336	0.0651
15	20	Biased	1.9688	1.9663	-0.0025
16	20	Unbiased	0.1326	0.0903	-0.0423
17	20	Biased	1.6054	1.5774	-0.028
18	20	Unbiased	0.3771	0.374	-0.0031
19	20	Biased	1.6983	1.6921	-0.0062
20	50	Unbiased	0.3044	0.3593	0.0549
21	0	Correlation	1.3952	1.3872	-0.008
22	50	Unbiased	-0.041	0.0442	0.0852
23	0	Correlation	0.6684	0.6522	-0.0162
24	20	Biased	1.263	1.2292	-0.0338
26	50	Biased	1.9272	2.0076	0.0804
27	30	Unbiased	1.5172	1.5426	0.0254
28	30	Biased	0.588	0.5836	-0.0044
29	30	Unbiased	0.9806	0.9635	-0.0171
30	20	Biased	2.9318	2.9174	-0.0144
31	30	Unbiased	2.019	2.0296	0.0106
33	30	Biased	0.7643	0.7681	0.0038
34	50	Unbiased	0.7879	0.9128	0.1249
35	20	Unbiased	-0.109	-0.088	0.021
41	30	Biased	1.9982	1.6754	-0.3228

Test Statistics (mV)

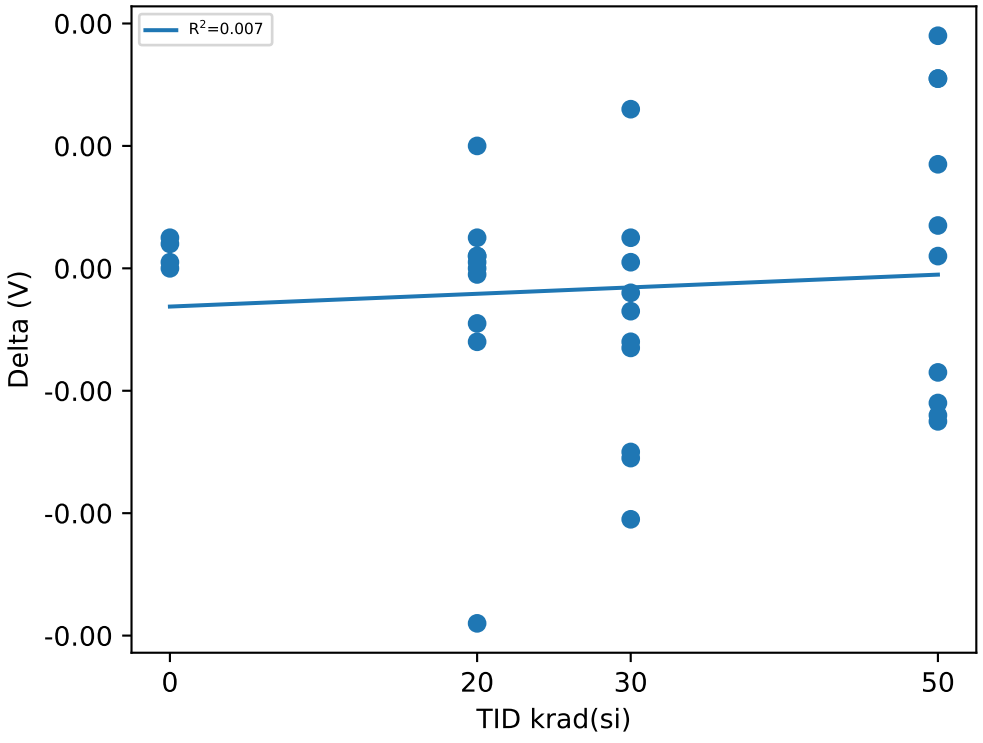
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.0972	0.73913	1.3952	0.53251	0.0942	0.7291	1.3872	0.53072	-0.0162	-0.010025	-0.003	0.0057691
20	-0.109	1.2602	2.9318	0.9648	-0.088	1.2533	2.9174	0.96479	-0.0423	-0.0069	0.0278	0.023265
30	0.588	1.4007	2.019	0.49988	0.5836	1.3746	2.0296	0.473	-0.3228	-0.02614	0.0295	0.10522
50	-0.5235	1.1252	2.4975	0.97886	-0.4598	1.1865	2.5221	0.9669	-0.0131	0.06125	0.1249	0.036534

Device Test: 19.31 VOLTAGE|VREF//12/12/0/0/5/100kHz//@VREF_25C

TID vs Result Stats



TID vs Post - Pre Exposure Delta



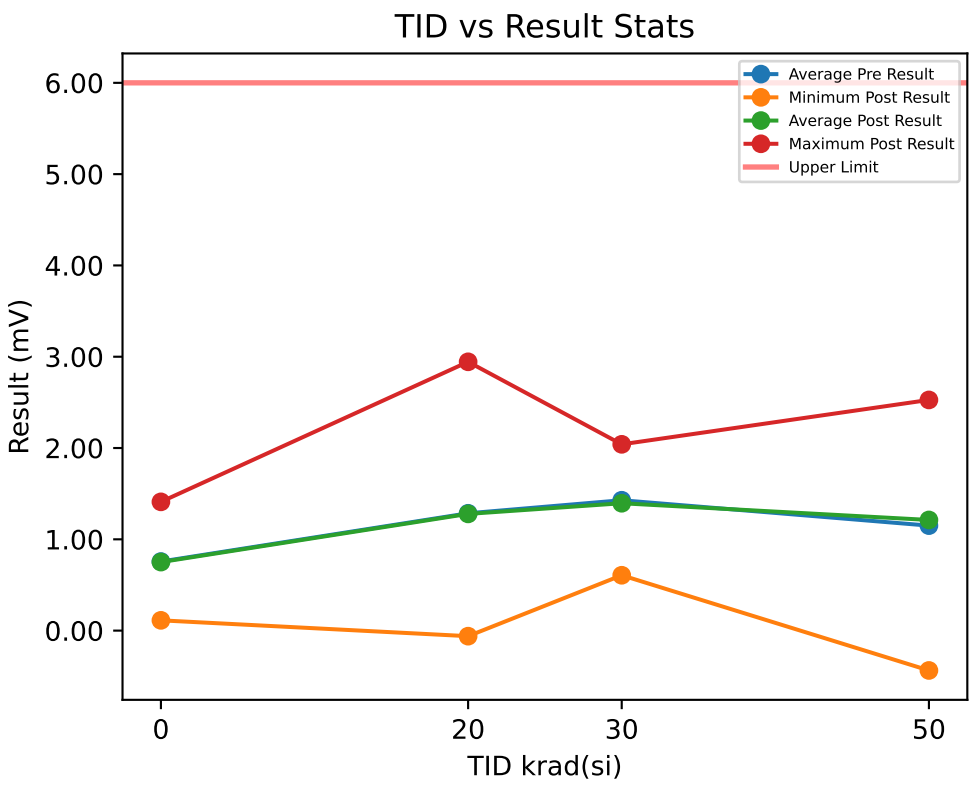
Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

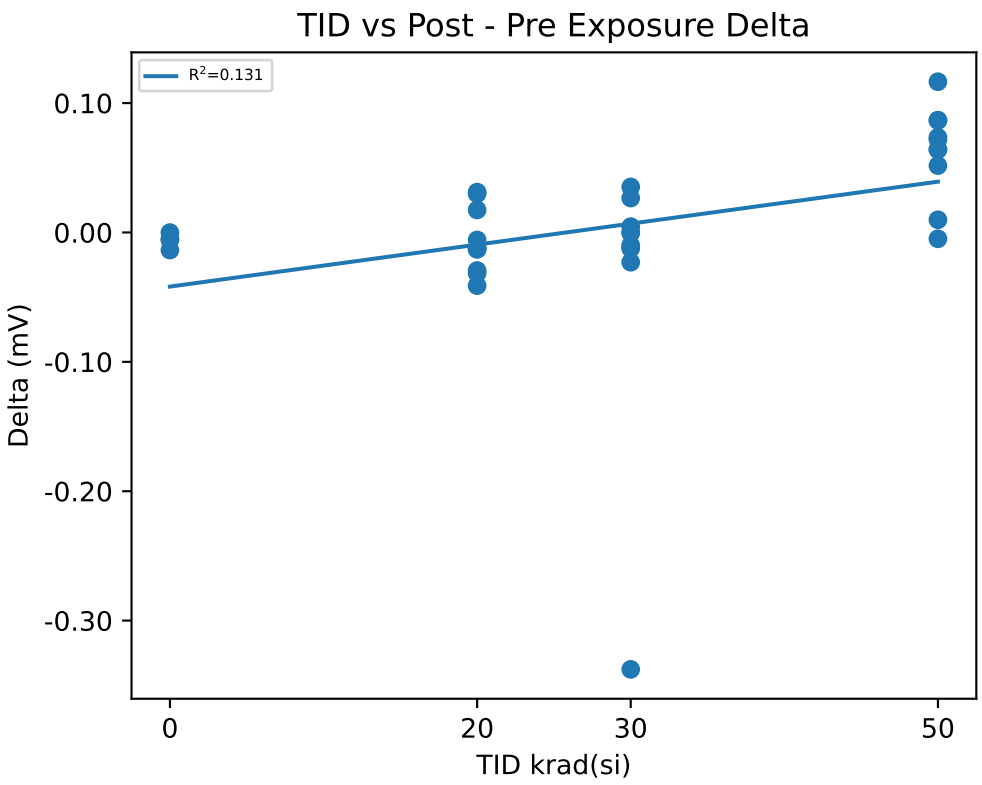
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	0.60011	0.60018	7e-05
2	20	Unbiased	0.60041	0.60043	2e-05
3	50	Biased	0.59972	0.59947	-0.00025
4	30	Unbiased	0.59994	0.59981	-0.00013
5	50	Unbiased	0.60029	0.60031	2e-05
6	30	Biased	0.59991	0.5996	-0.00031
7	50	Biased	0.59997	0.59973	-0.00024
8	30	Unbiased	0.5999	0.59949	-0.00041
9	20	Unbiased	0.59987	0.60007	0.0002
10	50	Biased	0.59972	0.5995	-0.00022
11	30	Biased	0.60049	0.60037	-0.00012
12	0	Correlation	0.60016	0.60016	0
13	0	Correlation	0.60036	0.60041	5e-05
14	50	Unbiased	0.59995	0.59978	-0.00017
15	20	Biased	0.60006	0.59994	-0.00012
16	20	Unbiased	0.60016	0.60016	0
17	20	Biased	0.60001	0.60006	5e-05
18	20	Unbiased	0.60049	0.59991	-0.00058
19	20	Biased	0.60037	0.60036	-1e-05
20	50	Unbiased	0.60039	0.60056	0.00017
21	0	Correlation	0.60016	0.6002	4e-05
22	50	Unbiased	0.60008	0.60046	0.00038
23	0	Correlation	0.60014	0.60015	1e-05
24	20	Biased	0.60046	0.60047	1e-05
26	50	Biased	0.60014	0.60045	0.00031
27	30	Unbiased	0.60008	0.60013	5e-05
28	30	Biased	0.60042	0.60012	-0.0003
29	30	Unbiased	0.60048	0.60041	-7e-05
30	20	Biased	0.59987	0.59989	2e-05
31	30	Unbiased	0.60044	0.60045	1e-05
33	30	Biased	0.60011	0.60007	-4e-05
34	50	Unbiased	0.60005	0.60036	0.00031
35	20	Unbiased	0.60041	0.60032	-9e-05
41	30	Biased	0.60028	0.60054	0.00026

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.60014	0.6002	0.60036	0.00010376	0.60015	0.60023	0.60041	0.00012193	0	2.5e-05	5e-05	2.3805e-05
20	0.59987	0.60021	0.60049	0.00024556	0.59989	0.60016	0.60047	0.00022022	-0.00058	-5e-05	0.0002	0.00020478
30	0.5999	0.6002	0.60049	0.00024469	0.59949	0.6001	0.60054	0.00036416	-0.00041	-0.000106	0.00026	0.00019716
50	0.59972	0.60004	0.60039	0.00021586	0.59947	0.60008	0.60056	0.0004182	-0.00025	3.8e-05	0.00038	0.00024805

Device Test: 19.33 VOLTAGE|OFFSET//12/12/0/0/5/100kHz//@EA_OS





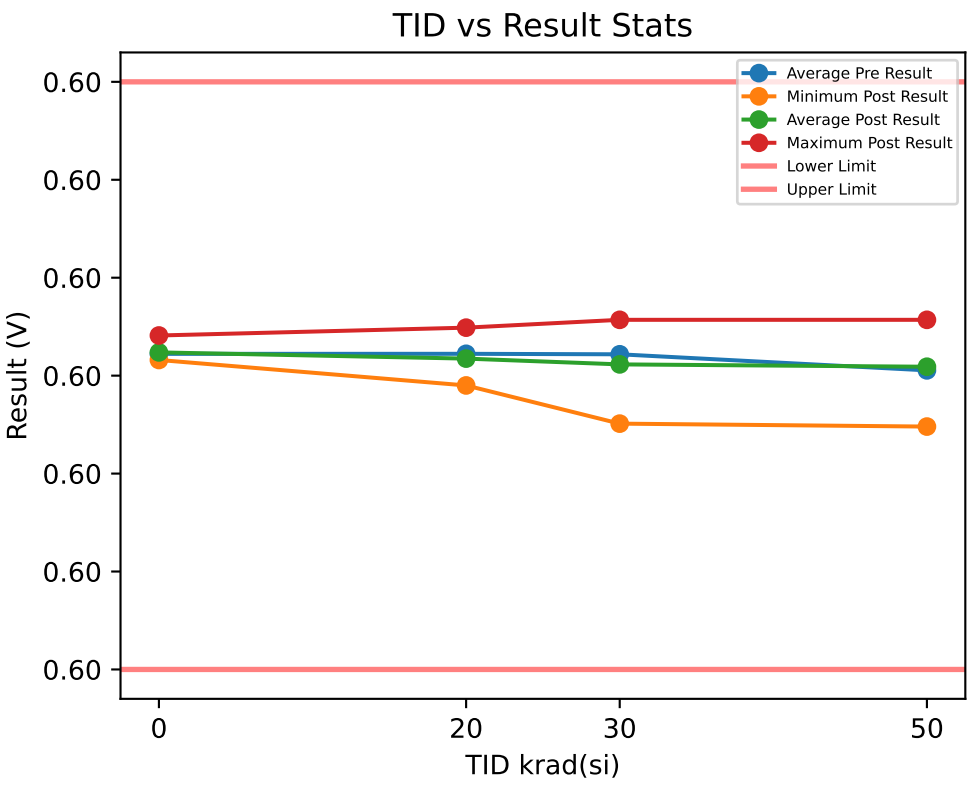
Test Results (Upper Limit = 6.0 (mV))

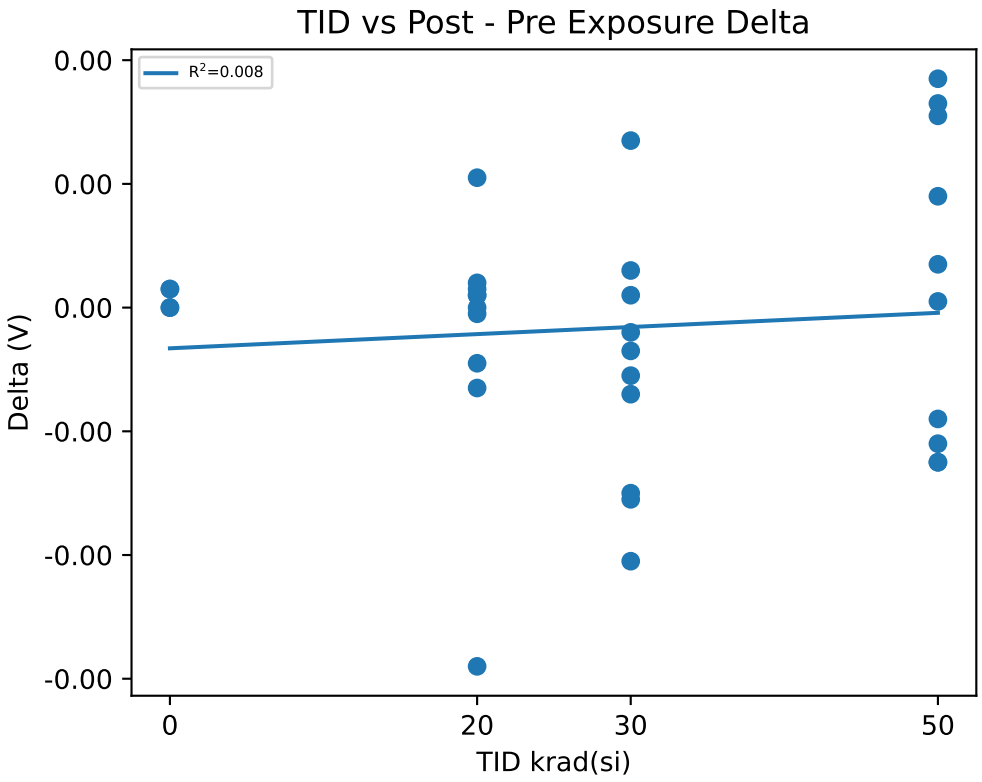
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	1.6362	1.6313	-0.0049
2	20	Unbiased	0.749	0.7664	0.0174
3	50	Biased	-0.5099	-0.4364	0.0735
4	30	Unbiased	1.321	1.3111	-0.0099
5	50	Unbiased	2.5169	2.5267	0.0098
6	30	Biased	1.3868	1.3913	0.0045
7	50	Biased	1.0593	1.1233	0.064
8	30	Unbiased	1.7501	1.7497	-0.0004
9	20	Unbiased	2.0307	2.0619	0.0312
10	50	Biased	1.8093	1.8735	0.0642
11	30	Biased	1.778	1.8046	0.0266
12	0	Correlation	0.8133	0.7997	-0.0136
13	0	Correlation	0.1127	0.1126	-0.0001
14	50	Unbiased	1.9004	1.9723	0.0719
15	20	Biased	2.0026	1.9898	-0.0128
16	20	Unbiased	0.1613	0.1202	-0.0411
17	20	Biased	1.623	1.5936	-0.0294
18	20	Unbiased	0.4107	0.3977	-0.013
19	20	Biased	1.7181	1.7123	-0.0058
20	50	Unbiased	0.3332	0.3849	0.0517
21	0	Correlation	1.4153	1.4103	-0.005
22	50	Unbiased	-0.018	0.0688	0.0868
23	0	Correlation	0.6856	0.6798	-0.0058
24	20	Biased	1.291	1.2594	-0.0316
26	50	Biased	1.9568	2.0434	0.0866
27	30	Unbiased	1.5365	1.5717	0.0352
28	30	Biased	0.6179	0.6063	-0.0116
29	30	Unbiased	1.006	0.983	-0.023
30	20	Biased	2.9568	2.9443	-0.0125
31	30	Unbiased	2.0528	2.0405	-0.0123
33	30	Biased	0.7952	0.7952	0
34	50	Unbiased	0.8165	0.933	0.1165
35	20	Unbiased	-0.0909	-0.0609	0.03
41	30	Biased	2.0353	1.6976	-0.3377

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.1127	0.75673	1.4153	0.5344	0.1126	0.7506	1.4103	0.53219	-0.0136	-0.006125	-0.0001	0.0055841
20	-0.0909	1.2852	2.9568	0.96467	-0.0609	1.2785	2.9443	0.96356	-0.0411	-0.00676	0.0312	0.025373
30	0.6179	1.428	2.0528	0.49946	0.6063	1.3951	2.0405	0.47042	-0.3377	-0.03286	0.0352	0.10859
50	-0.5099	1.1501	2.5169	0.98091	-0.4364	1.2121	2.5267	0.96638	-0.0049	0.06201	0.1165	0.036111

Device Test: 19.34 VOLTAGE|VREF//14/14/0/0/5/100kHz//@VREF_25C





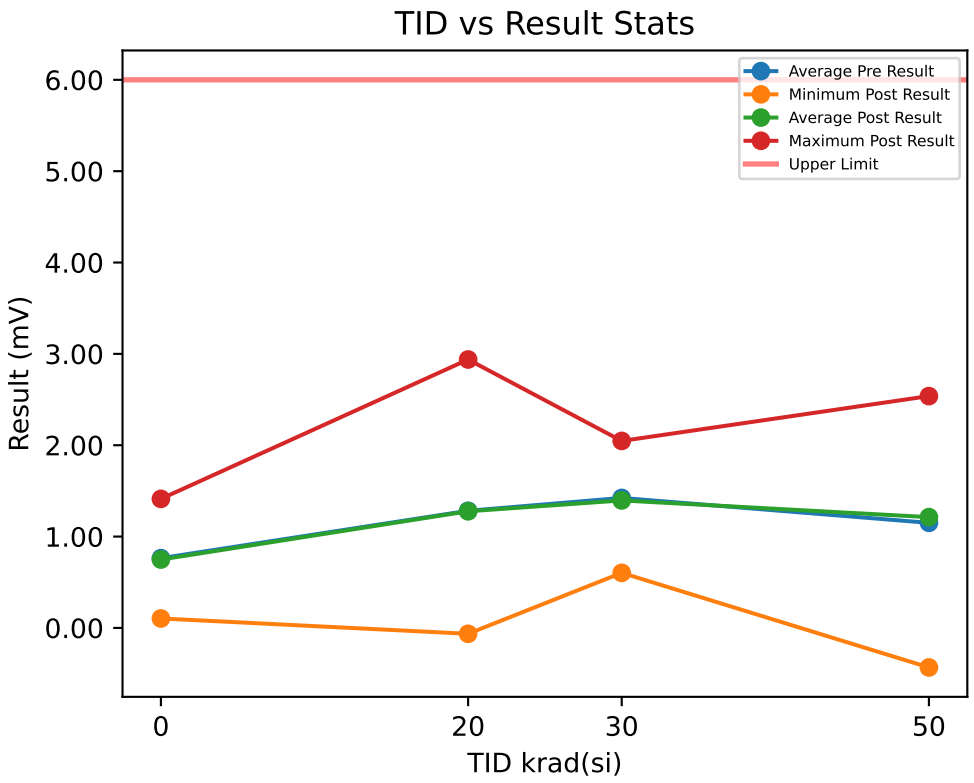
Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

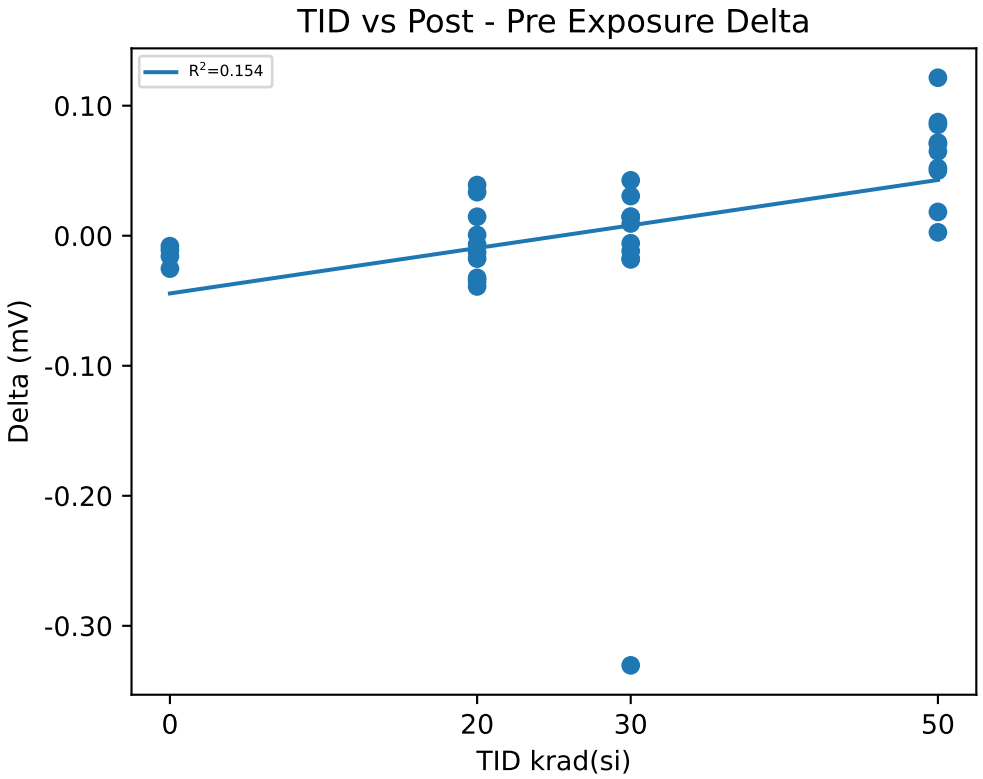
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	0.60013	0.6002	7e-05
2	20	Unbiased	0.60043	0.60045	2e-05
3	50	Biased	0.59973	0.59948	-0.00025
4	30	Unbiased	0.59996	0.59982	-0.00014
5	50	Unbiased	0.60031	0.60032	1e-05
6	30	Biased	0.59992	0.59962	-0.0003
7	50	Biased	0.59999	0.59974	-0.00025
8	30	Unbiased	0.59992	0.59951	-0.00041
9	20	Unbiased	0.59987	0.60008	0.00021
10	50	Biased	0.59973	0.59951	-0.00022
11	30	Biased	0.6005	0.60039	-0.00011
12	0	Correlation	0.60017	0.60017	0
13	0	Correlation	0.60038	0.60041	3e-05
14	50	Unbiased	0.59997	0.59979	-0.00018
15	20	Biased	0.60008	0.59995	-0.00013
16	20	Unbiased	0.60017	0.60017	0
17	20	Biased	0.60003	0.60007	4e-05
18	20	Unbiased	0.6005	0.59992	-0.00058
19	20	Biased	0.60039	0.60038	-1e-05
20	50	Unbiased	0.60039	0.60057	0.00018
21	0	Correlation	0.60018	0.60021	3e-05
22	50	Unbiased	0.60009	0.60046	0.00037
23	0	Correlation	0.60016	0.60016	0
24	20	Biased	0.60047	0.60049	2e-05
26	50	Biased	0.60015	0.60046	0.00031
27	30	Unbiased	0.60009	0.60015	6e-05
28	30	Biased	0.60044	0.60013	-0.00031
29	30	Unbiased	0.60049	0.60042	-7e-05
30	20	Biased	0.59987	0.5999	3e-05
31	30	Unbiased	0.60044	0.60046	2e-05
33	30	Biased	0.60012	0.60008	-4e-05
34	50	Unbiased	0.60005	0.60038	0.00033
35	20	Unbiased	0.60042	0.60033	-9e-05
41	30	Biased	0.6003	0.60057	0.00027

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.60016	0.60022	0.60038	0.00010532	0.60016	0.60024	0.60041	0.00011701	0	1.5e-05	3e-05	1.7321e-05
20	0.59987	0.60022	0.6005	0.00024878	0.5999	0.60017	0.60049	0.00022416	-0.00058	-4.9e-05	0.00021	0.0002068
30	0.59992	0.60022	0.6005	0.00024243	0.59951	0.60011	0.60057	0.00036446	-0.00041	-0.000103	0.00027	0.00020089
50	0.59973	0.60005	0.60039	0.00021495	0.59948	0.60009	0.60057	0.00041824	-0.00025	3.7e-05	0.00037	0.00025197

Device Test: 19.36 VOLTAGE|OFFSET//14/14/0/0/5/100kHz//@EA_OS





Test Results (Upper Limit = 6.0 (mV))

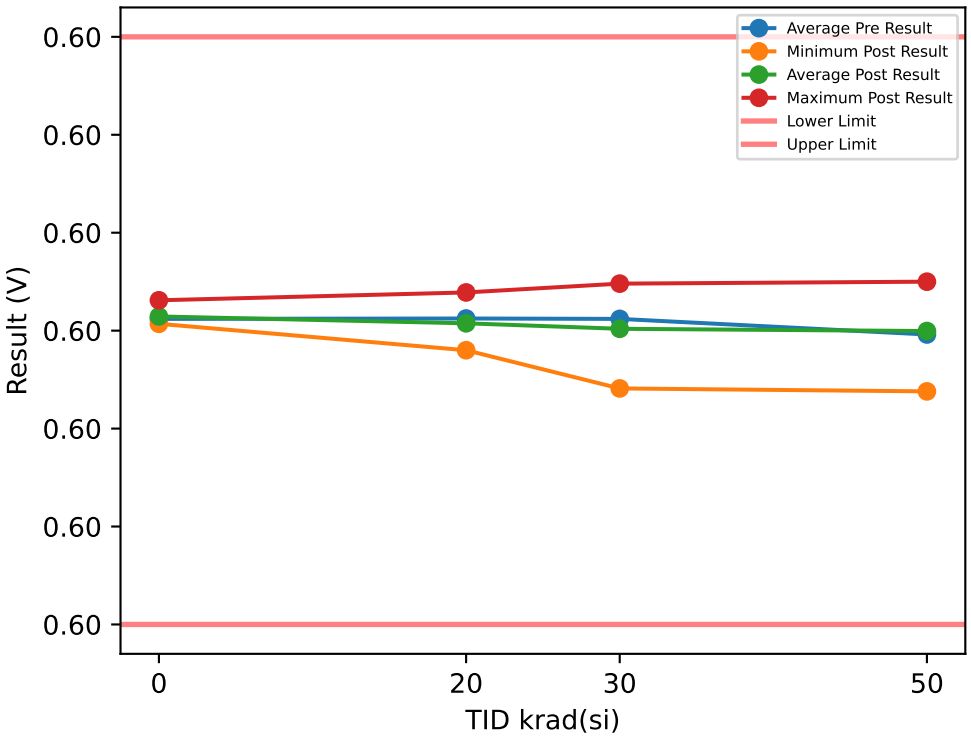
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	1.6324	1.635	0.0026
2	20	Unbiased	0.7579	0.7725	0.0146
3	50	Biased	-0.5035	-0.4329	0.0706
4	30	Unbiased	1.3144	1.3026	-0.0118
5	50	Unbiased	2.5194	2.5377	0.0183
6	30	Biased	1.3762	1.3909	0.0147
7	50	Biased	1.0651	1.1152	0.0501
8	30	Unbiased	1.7618	1.756	-0.0058
9	20	Unbiased	2.0197	2.0587	0.039
10	50	Biased	1.8131	1.878	0.0649
11	30	Biased	1.7722	1.8027	0.0305
12	0	Correlation	0.8121	0.7963	-0.0158
13	0	Correlation	0.1288	0.1035	-0.0253
14	50	Unbiased	1.8905	1.9621	0.0716
15	20	Biased	1.9997	1.9821	-0.0176
16	20	Unbiased	0.1579	0.1189	-0.039
17	20	Biased	1.6284	1.5935	-0.0349
18	20	Unbiased	0.4017	0.3888	-0.0129
19	20	Biased	1.7168	1.7174	0.0006
20	50	Unbiased	0.3326	0.3846	0.052
21	0	Correlation	1.4206	1.4126	-0.008
22	50	Unbiased	-0.02	0.0653	0.0853
23	0	Correlation	0.6929	0.6819	-0.011
24	20	Biased	1.2945	1.2621	-0.0324
26	50	Biased	1.9553	2.0427	0.0874
27	30	Unbiased	1.5272	1.5698	0.0426
28	30	Biased	0.6205	0.6028	-0.0177
29	30	Unbiased	0.9985	0.9803	-0.0182
30	20	Biased	2.9451	2.9384	-0.0067
31	30	Unbiased	2.0375	2.0469	0.0094
33	30	Biased	0.7841	0.7985	0.0144
34	50	Unbiased	0.8189	0.9404	0.1215
35	20	Unbiased	-0.0978	-0.0643	0.0335
41	30	Biased	2.0356	1.7052	-0.3304

Test Statistics (mV)

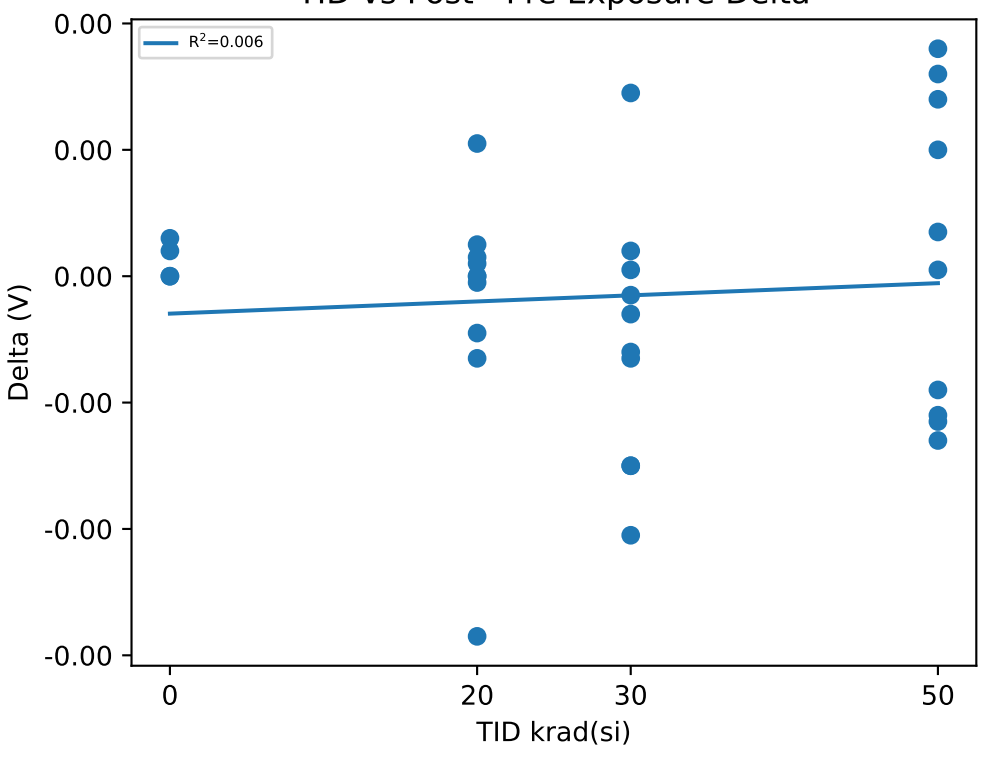
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.1288	0.7636	1.4206	0.52977	0.1035	0.74857	1.4126	0.53659	-0.0253	-0.015025	-0.008	0.0075659
20	-0.0978	1.2824	2.9451	0.9633	-0.0643	1.2768	2.9384	0.96301	-0.039	-0.00558	0.039	0.027599
30	0.6205	1.4228	2.0375	0.49965	0.6028	1.3956	2.0469	0.47284	-0.3304	-0.02723	0.0426	0.10844
50	-0.5035	1.1504	2.5194	0.97937	-0.4329	1.2128	2.5377	0.9673	0.0026	0.06243	0.1215	0.034287

Device Test: 19.37 VOLTAGE|VREF//4.5/4.5/0/0/4.5/500kHz//@VREF_25C

TID vs Result Stats



TID vs Post - Pre Exposure Delta



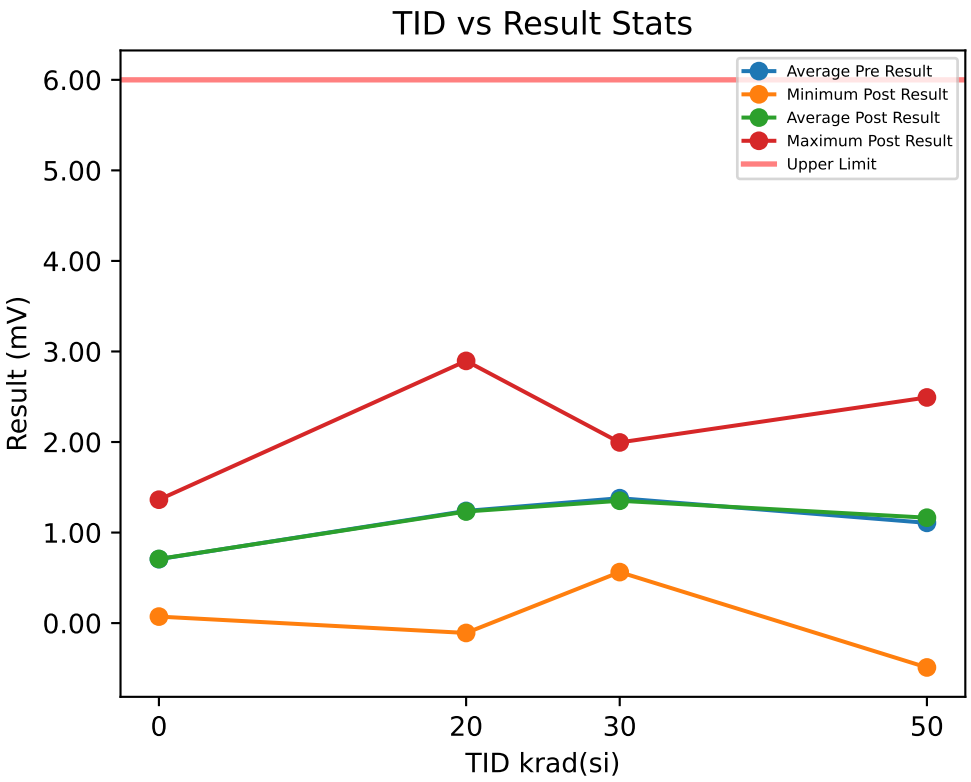
Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

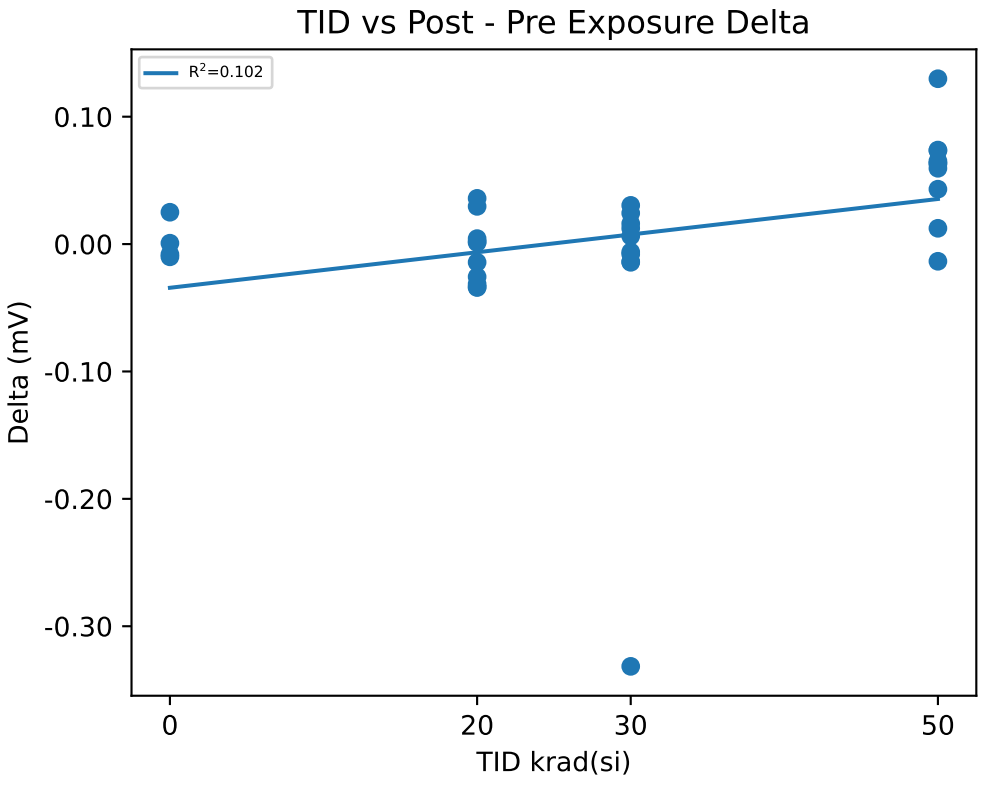
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	0.60003	0.6001	7e-05
2	20	Unbiased	0.60035	0.60035	0
3	50	Biased	0.59964	0.59938	-0.00026
4	30	Unbiased	0.59985	0.59973	-0.00012
5	50	Unbiased	0.60022	0.60023	1e-05
6	30	Biased	0.59983	0.59953	-0.0003
7	50	Biased	0.59987	0.59964	-0.00023
8	30	Unbiased	0.59982	0.59941	-0.00041
9	20	Unbiased	0.59978	0.59999	0.00021
10	50	Biased	0.59963	0.59941	-0.00022
11	30	Biased	0.60041	0.60028	-0.00013
12	0	Correlation	0.60008	0.60008	0
13	0	Correlation	0.60025	0.60031	6e-05
14	50	Unbiased	0.59989	0.59971	-0.00018
15	20	Biased	0.59999	0.59986	-0.00013
16	20	Unbiased	0.60006	0.60006	0
17	20	Biased	0.59993	0.59998	5e-05
18	20	Unbiased	0.60039	0.59982	-0.00057
19	20	Biased	0.60029	0.60028	-1e-05
20	50	Unbiased	0.6003	0.6005	0.0002
21	0	Correlation	0.60008	0.60012	4e-05
22	50	Unbiased	0.60001	0.60037	0.00036
23	0	Correlation	0.60007	0.60007	0
24	20	Biased	0.60036	0.60039	3e-05
26	50	Biased	0.60007	0.60035	0.00028
27	30	Unbiased	0.60001	0.60005	4e-05
28	30	Biased	0.60033	0.60003	-0.0003
29	30	Unbiased	0.60038	0.60032	-6e-05
30	20	Biased	0.59978	0.5998	2e-05
31	30	Unbiased	0.60036	0.60037	1e-05
33	30	Biased	0.60002	0.59999	-3e-05
34	50	Unbiased	0.59995	0.60027	0.00032
35	20	Unbiased	0.60031	0.60022	-9e-05
41	30	Biased	0.60019	0.60048	0.00029

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.60007	0.60012	0.60025	8.6795e-05	0.60007	0.60014	0.60031	0.0001121	0	2.5e-05	6e-05	3e-05
20	0.59978	0.60012	0.60039	0.00024405	0.5998	0.60008	0.60039	0.00022142	-0.00057	-4.9e-05	0.00021	0.00020382
30	0.59982	0.60012	0.60041	0.00024207	0.59941	0.60002	0.60048	0.00036361	-0.00041	-0.000101	0.00029	0.00020212
50	0.59963	0.59996	0.6003	0.00021784	0.59938	0.6	0.6005	0.00042048	-0.00026	3.5e-05	0.00036	0.00024596

Device Test: 19.39 VOLTAGE|OFFSET//4.5/4.5/0/0/4.5/500kHz//@EA_OS





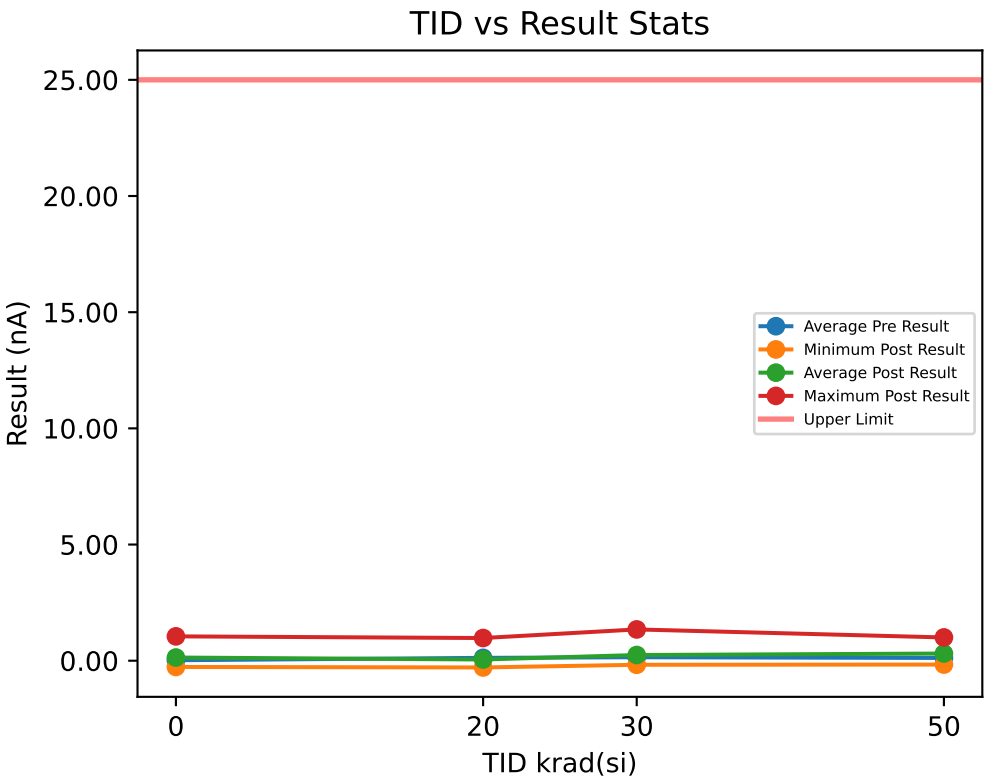
Test Results (Upper Limit = 6.0 (mV))

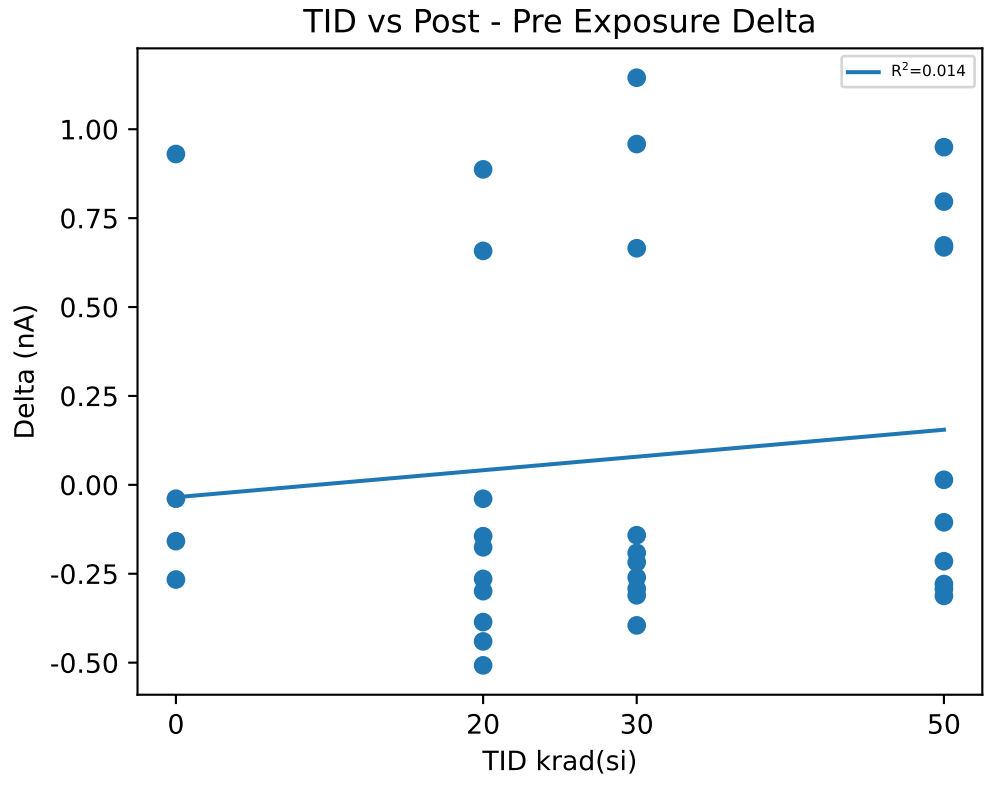
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	1.5938	1.5803	-0.0135
2	20	Unbiased	0.7222	0.7234	0.0012
3	50	Biased	-0.5329	-0.4898	0.0431
4	30	Unbiased	1.2638	1.2701	0.0063
5	50	Unbiased	2.4798	2.4922	0.0124
6	30	Biased	1.3386	1.3547	0.0161
7	50	Biased	1.0047	1.0781	0.0734
8	30	Unbiased	1.7191	1.7048	-0.0143
9	20	Unbiased	1.9784	2.0143	0.0359
10	50	Biased	1.7664	1.8298	0.0634
11	30	Biased	1.7392	1.7635	0.0243
12	0	Correlation	0.7684	0.7584	-0.01
13	0	Correlation	0.047	0.072	0.025
14	50	Unbiased	1.8529	1.9161	0.0632
15	20	Biased	1.9631	1.9374	-0.0257
16	20	Unbiased	0.1079	0.0738	-0.0341
17	20	Biased	1.5813	1.5477	-0.0336
18	20	Unbiased	0.3542	0.3562	0.002
19	20	Biased	1.6765	1.6808	0.0043
20	50	Unbiased	0.2788	0.3383	0.0595
21	0	Correlation	1.3711	1.363	-0.0081
22	50	Unbiased	-0.0526	0.0126	0.0652
23	0	Correlation	0.6392	0.6399	0.0007
24	20	Biased	1.2354	1.204	-0.0314
26	50	Biased	1.9237	1.9975	0.0738
27	30	Unbiased	1.4918	1.5222	0.0304
28	30	Biased	0.5695	0.5633	-0.0062
29	30	Unbiased	0.9524	0.9386	-0.0138
30	20	Biased	2.9102	2.8959	-0.0143
31	30	Unbiased	2.0032	1.9953	-0.0079
33	30	Biased	0.738	0.7504	0.0124
34	50	Unbiased	0.7573	0.8871	0.1298
35	20	Unbiased	-0.1384	-0.1088	0.0296
41	30	Biased	1.9805	1.649	-0.3315

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.047	0.70642	1.3711	0.54314	0.072	0.70832	1.363	0.52937	-0.01	0.0019	0.025	0.01609
20	-0.1384	1.2391	2.9102	0.96604	-0.1088	1.2325	2.8959	0.96292	-0.0341	-0.00661	0.0359	0.025592
30	0.5695	1.3796	2.0032	0.50251	0.5633	1.3512	1.9953	0.4698	-0.3315	-0.02842	0.0304	0.10764
50	-0.5329	1.1072	2.4798	0.97936	-0.4898	1.1642	2.4922	0.96998	-0.0135	0.05703	0.1298	0.038234

Device Test: 19.4 CURRENT|EA//4.5/4.5/0/0/4.5/500kHz//@EA_IB





Test Results (Upper Limit = 25.0 (nA))

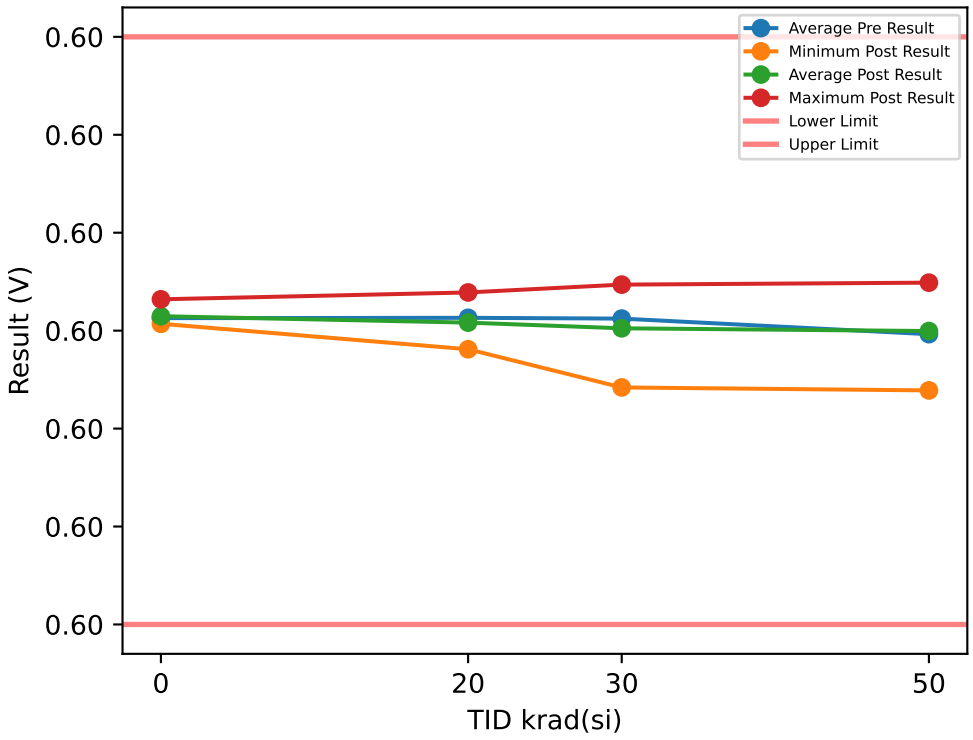
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	0.2151	0.8829	0.6678
2	20	Unbiased	0.2157	0.8735	0.6578
3	50	Biased	0.0739	0.8704	0.7965
4	30	Unbiased	0.1646	-0.0958	-0.2604
5	50	Unbiased	-0.0255	-0.0113	0.0142
6	30	Biased	0.1533	-0.0643	-0.2176
7	50	Biased	0.052	1.0016	0.9496
8	30	Unbiased	0.2207	-0.1745	-0.3952
9	20	Unbiased	-0.0629	-0.102	-0.0391
10	50	Biased	0.0347	-0.0706	-0.1053
11	30	Biased	0.077	-0.1143	-0.1913
12	0	Correlation	0.2145	-0.0518	-0.2663
13	0	Correlation	0.1182	1.0485	0.9303
14	50	Unbiased	0.1908	-0.102	-0.2928
15	20	Biased	0.0582	-0.1174	-0.1756
16	20	Unbiased	0.1958	-0.1901	-0.3859
17	20	Biased	0.1526	-0.1464	-0.299
18	20	Unbiased	0.1502	-0.29	-0.4402
19	20	Biased	0.0895	0.9766	0.8871
20	50	Unbiased	0.2207	-0.0583	-0.279
21	0	Correlation	-0.1098	-0.2681	-0.1583
22	50	Unbiased	0.0971	-0.1176	-0.2147
23	0	Correlation	-0.1417	-0.1807	-0.039
24	20	Biased	0.2332	-0.2744	-0.5076
26	50	Biased	0.1471	-0.1651	-0.3122
27	30	Unbiased	0.1082	-0.0334	-0.1416
28	30	Biased	0.2519	0.9172	0.6653
29	30	Unbiased	-0.0567	0.9016	0.9583
30	20	Biased	0.1065	-0.158	-0.2645
31	30	Unbiased	0.1332	-0.1589	-0.2921
33	30	Biased	0.24	-0.0706	-0.3106
34	50	Unbiased	0.1845	0.8579	0.6734
35	20	Unbiased	0.0957	-0.0487	-0.1444
41	30	Biased	0.2017	1.3465	1.1448

Test Statistics (nA)

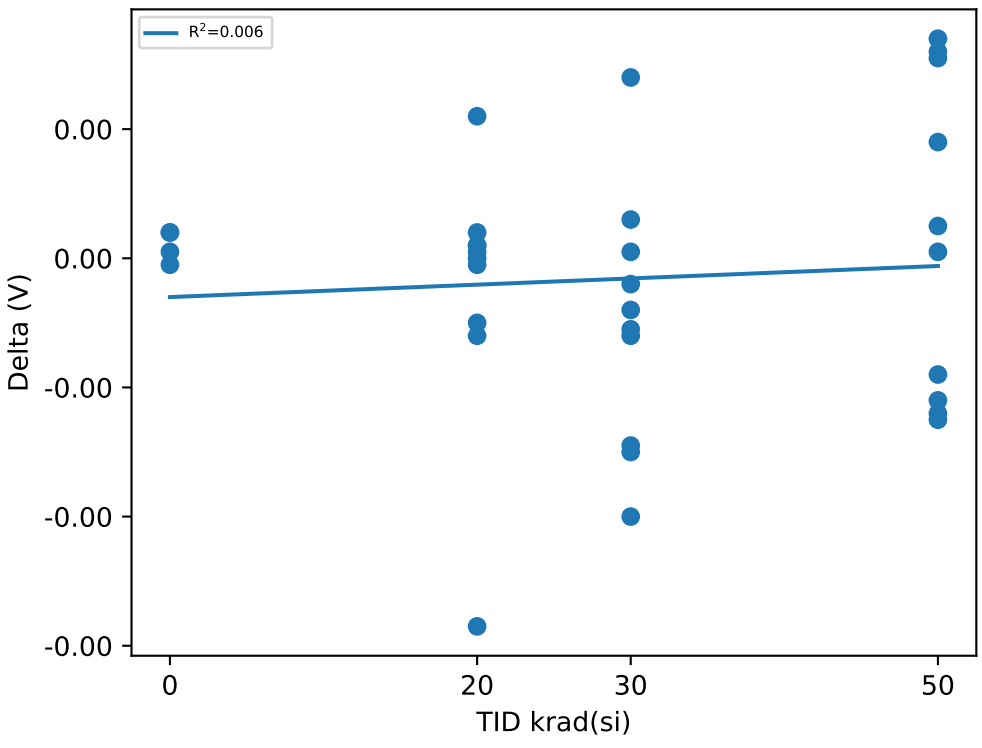
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.1417	0.0203	0.2145	0.17365	-0.2681	0.13698	1.0485	0.61414	-0.2663	0.11668	0.9303	0.5503
20	-0.0629	0.12345	0.2332	0.087273	-0.29	0.05231	0.9766	0.46641	-0.5076	-0.07114	0.8871	0.46927
30	-0.0567	0.14939	0.2519	0.092171	-0.1745	0.24535	1.3465	0.57285	-0.3952	0.09596	1.1448	0.58587
50	-0.0255	0.11904	0.2207	0.084854	-0.1651	0.30879	1.0016	0.51454	-0.3122	0.18975	0.9496	0.51575

Device Test: 19.40 VOLTAGE|VREF//5/5/0/0/5/500kHz//@VREF_25C

TID vs Result Stats



TID vs Post - Pre Exposure Delta



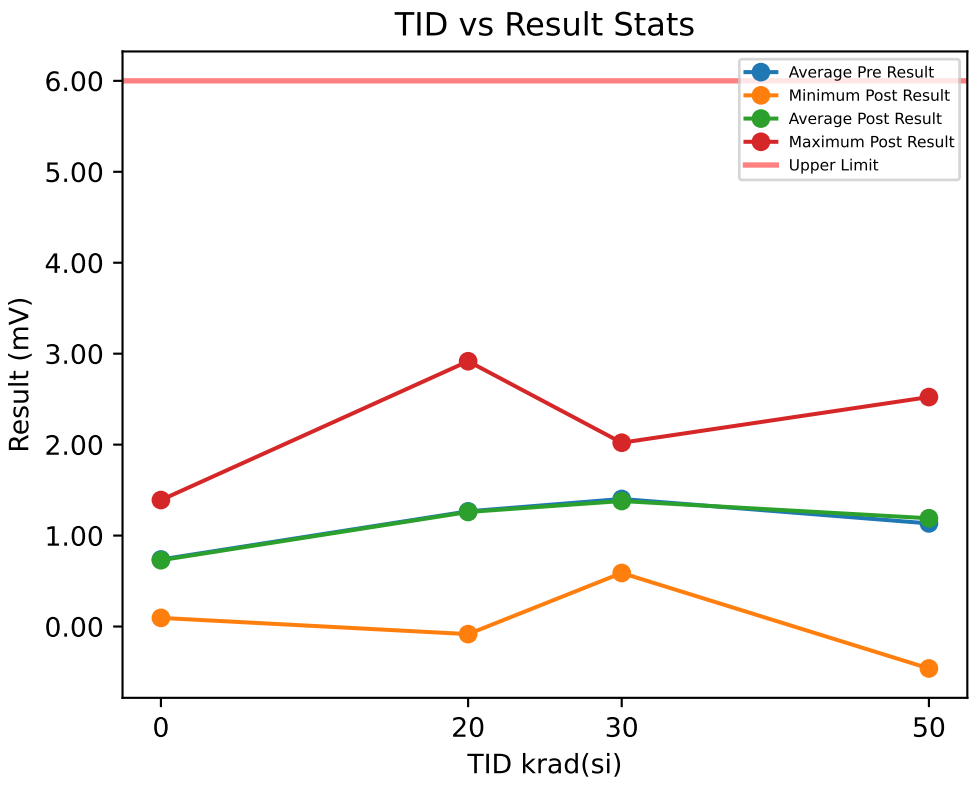
Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

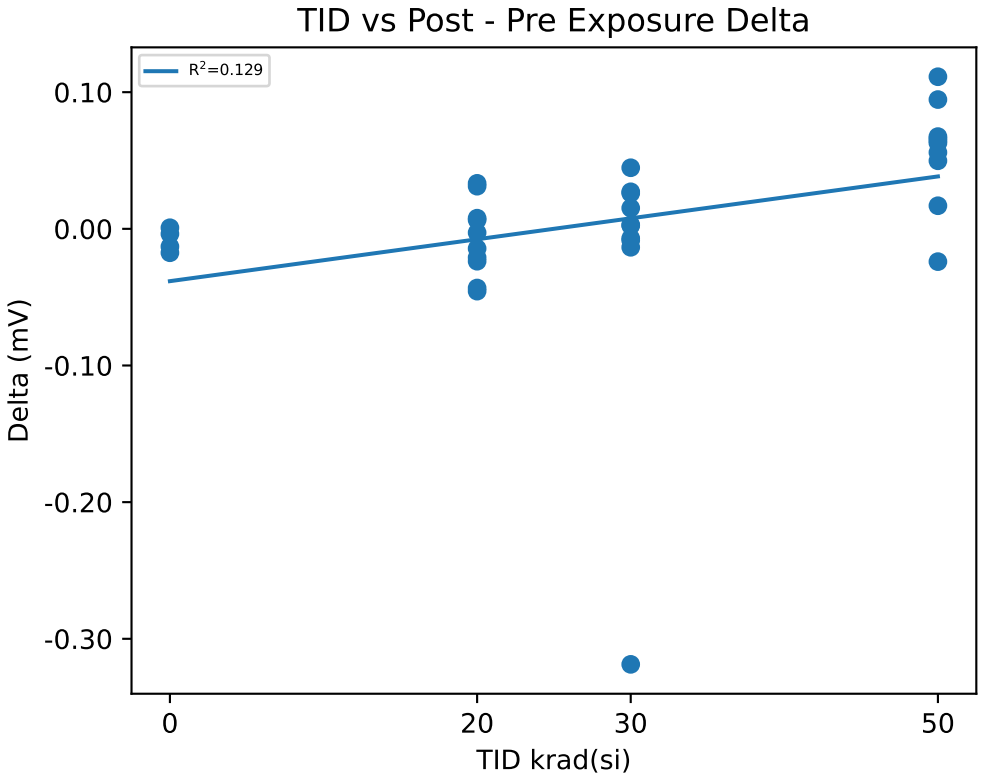
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	0.60004	0.60009	5e-05
2	20	Unbiased	0.60034	0.60035	1e-05
3	50	Biased	0.59964	0.59939	-0.00025
4	30	Unbiased	0.59985	0.59974	-0.00011
5	50	Unbiased	0.60022	0.60023	1e-05
6	30	Biased	0.59982	0.59953	-0.00029
7	50	Biased	0.59989	0.59965	-0.00024
8	30	Unbiased	0.59982	0.59942	-0.0004
9	20	Unbiased	0.59978	0.6	0.00022
10	50	Biased	0.59963	0.59941	-0.00022
11	30	Biased	0.60041	0.60029	-0.00012
12	0	Correlation	0.60007	0.60008	1e-05
13	0	Correlation	0.60028	0.60032	4e-05
14	50	Unbiased	0.59987	0.59969	-0.00018
15	20	Biased	0.59998	0.59986	-0.00012
16	20	Unbiased	0.60008	0.60008	0
17	20	Biased	0.59994	0.59998	4e-05
18	20	Unbiased	0.60041	0.59984	-0.00057
19	20	Biased	0.60029	0.60028	-1e-05
20	50	Unbiased	0.60031	0.60049	0.00018
21	0	Correlation	0.60008	0.60012	4e-05
22	50	Unbiased	0.60001	0.60035	0.00034
23	0	Correlation	0.60008	0.60007	-1e-05
24	20	Biased	0.60037	0.60039	2e-05
26	50	Biased	0.60006	0.60038	0.00032
27	30	Unbiased	0.6	0.60006	6e-05
28	30	Biased	0.60035	0.60005	-0.0003
29	30	Unbiased	0.6004	0.60032	-8e-05
30	20	Biased	0.59979	0.59981	2e-05
31	30	Unbiased	0.60036	0.60037	1e-05
33	30	Biased	0.60003	0.59999	-4e-05
34	50	Unbiased	0.59997	0.60028	0.00031
35	20	Unbiased	0.60033	0.60023	-0.0001
41	30	Biased	0.60019	0.60047	0.00028

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.60007	0.60013	0.60028	0.00010178	0.60007	0.60015	0.60032	0.00011701	-1e-05	2e-05	4e-05	2.4495e-05
20	0.59978	0.60013	0.60041	0.00024606	0.59981	0.60008	0.60039	0.00021776	-0.00057	-4.9e-05	0.00022	0.00020447
30	0.59982	0.60012	0.60041	0.00024793	0.59942	0.60002	0.60047	0.0003605	-0.0004	-9.9e-05	0.00028	0.00019796
50	0.59963	0.59996	0.60031	0.0002194	0.59939	0.6	0.60049	0.00041966	-0.00025	3.2e-05	0.00034	0.00024489

Device Test: 19.42 VOLTAGE|OFFSET//5/5/0/0/5/500kHz//@EA_OS





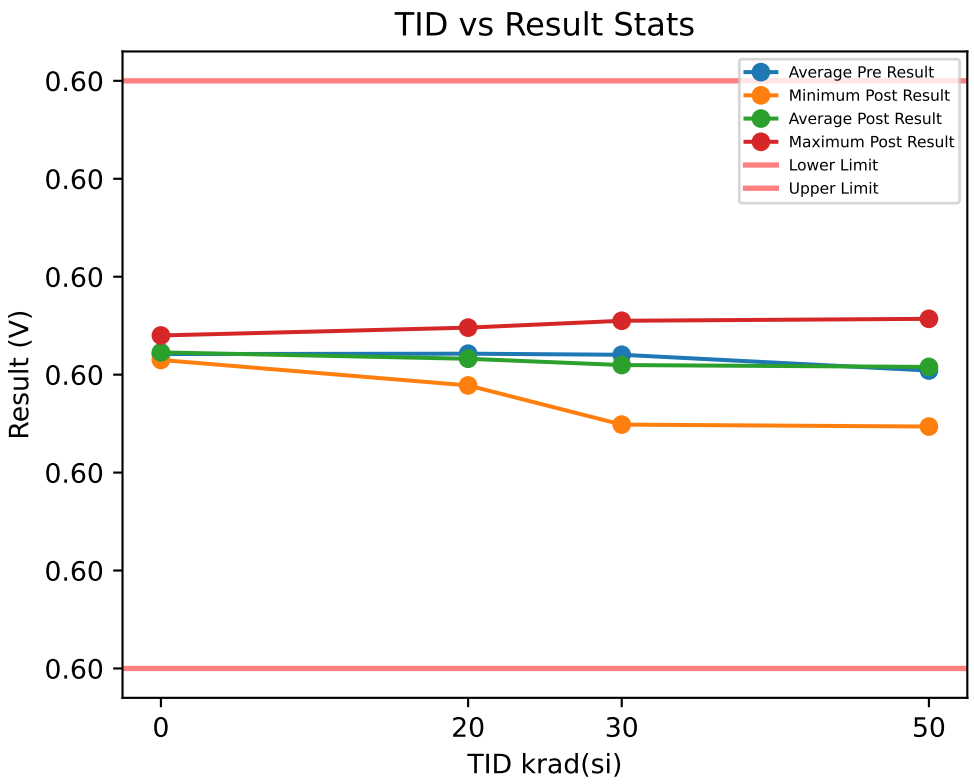
Test Results (Upper Limit = 6.0 (mV))

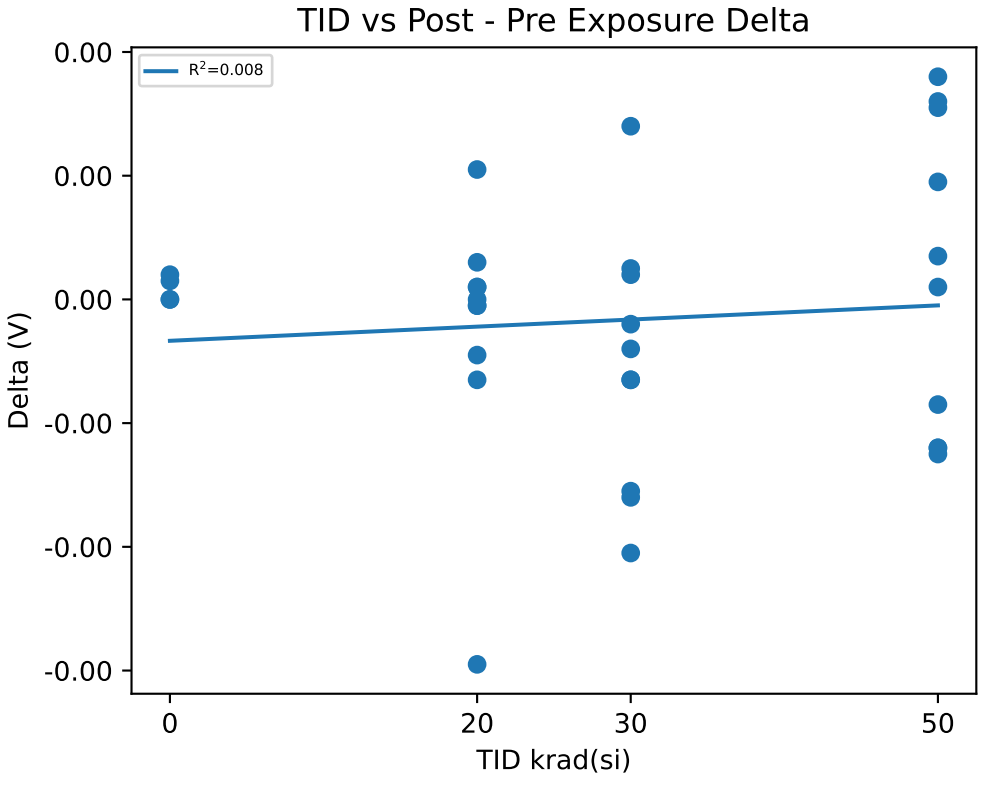
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	1.6223	1.5983	-0.024
2	20	Unbiased	0.7431	0.7496	0.0065
3	50	Biased	-0.5169	-0.461	0.0559
4	30	Unbiased	1.2956	1.298	0.0024
5	50	Unbiased	2.5063	2.5232	0.0169
6	30	Biased	1.3575	1.3836	0.0261
7	50	Biased	1.0374	1.1018	0.0644
8	30	Unbiased	1.7353	1.7382	0.0029
9	20	Unbiased	2.0066	2.0399	0.0333
10	50	Biased	1.7916	1.8591	0.0675
11	30	Biased	1.7584	1.7855	0.0271
12	0	Correlation	0.7874	0.7744	-0.013
13	0	Correlation	0.0987	0.095	-0.0037
14	50	Unbiased	1.8738	1.9399	0.0661
15	20	Biased	1.9862	1.9718	-0.0144
16	20	Unbiased	0.1438	0.0982	-0.0456
17	20	Biased	1.6158	1.5725	-0.0433
18	20	Unbiased	0.3837	0.3809	-0.0028
19	20	Biased	1.698	1.7058	0.0078
20	50	Unbiased	0.3143	0.3641	0.0498
21	0	Correlation	1.3899	1.3907	0.0008
22	50	Unbiased	-0.0271	0.0357	0.0628
23	0	Correlation	0.6737	0.6562	-0.0175
24	20	Biased	1.2661	1.2424	-0.0237
26	50	Biased	1.9359	2.0305	0.0946
27	30	Unbiased	1.5092	1.5539	0.0447
28	30	Biased	0.5973	0.5889	-0.0084
29	30	Unbiased	0.9846	0.9711	-0.0135
30	20	Biased	2.9379	2.9169	-0.021
31	30	Unbiased	2.0279	2.021	-0.0069
33	30	Biased	0.7651	0.7803	0.0152
34	50	Unbiased	0.8001	0.9114	0.1113
35	20	Unbiased	-0.1146	-0.0834	0.0312
41	30	Biased	1.9955	1.6768	-0.3187

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.0987	0.73742	1.3899	0.52923	0.095	0.72908	1.3907	0.5314	-0.0175	-0.00835	0.0008	0.0083803
20	-0.1146	1.2667	2.9379	0.96544	-0.0834	1.2595	2.9169	0.96291	-0.0456	-0.0072	0.0333	0.027566
30	0.5973	1.4026	2.0279	0.49825	0.5889	1.3797	2.021	0.4692	-0.3187	-0.02291	0.0447	0.10556
50	-0.5169	1.1338	2.5063	0.97814	-0.461	1.1903	2.5232	0.97104	-0.024	0.05653	0.1113	0.037806

Device Test: 19.43 VOLTAGE|VREF//12/12/0/0/5/500kHz//@VREF_25C





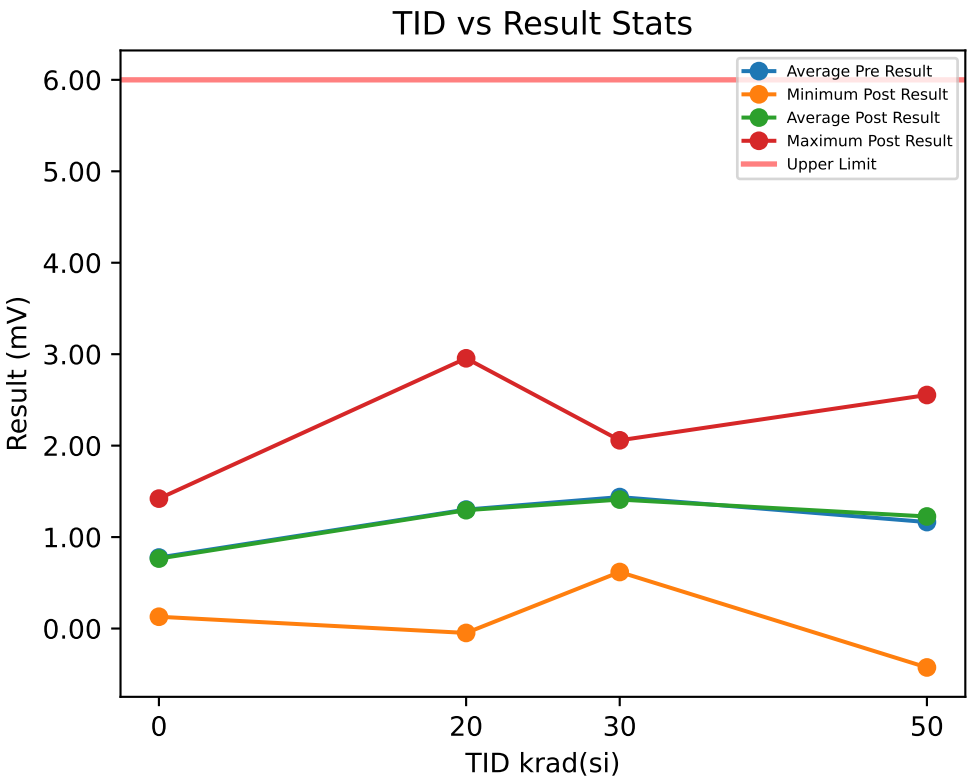
Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

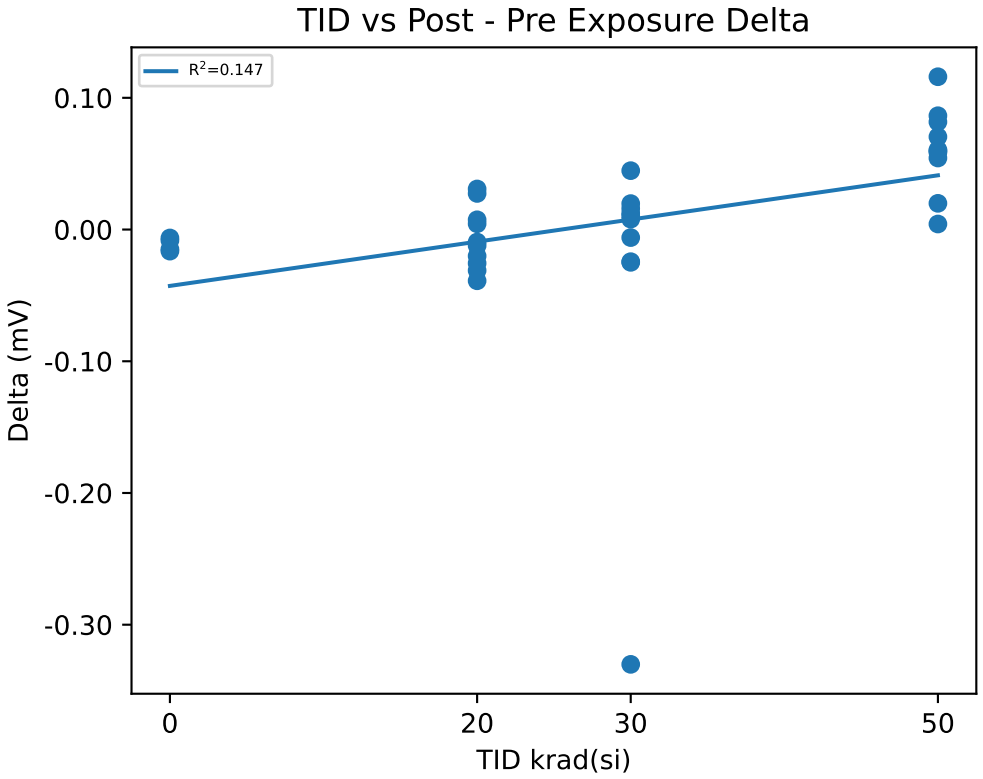
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	0.60011	0.60018	7e-05
2	20	Unbiased	0.60043	0.60043	0
3	50	Biased	0.59972	0.59947	-0.00025
4	30	Unbiased	0.59994	0.59981	-0.00013
5	50	Unbiased	0.60029	0.60031	2e-05
6	30	Biased	0.59991	0.5996	-0.00031
7	50	Biased	0.59996	0.59972	-0.00024
8	30	Unbiased	0.5999	0.59949	-0.00041
9	20	Unbiased	0.59986	0.60007	0.00021
10	50	Biased	0.59972	0.59948	-0.00024
11	30	Biased	0.60049	0.60036	-0.00013
12	0	Correlation	0.60016	0.60016	0
13	0	Correlation	0.60037	0.6004	3e-05
14	50	Unbiased	0.59996	0.59979	-0.00017
15	20	Biased	0.60006	0.59993	-0.00013
16	20	Unbiased	0.60016	0.60015	-1e-05
17	20	Biased	0.60001	0.60007	6e-05
18	20	Unbiased	0.6005	0.59991	-0.00059
19	20	Biased	0.60037	0.60036	-1e-05
20	50	Unbiased	0.60038	0.60057	0.00019
21	0	Correlation	0.60016	0.6002	4e-05
22	50	Unbiased	0.60009	0.60045	0.00036
23	0	Correlation	0.60015	0.60015	0
24	20	Biased	0.60046	0.60048	2e-05
26	50	Biased	0.60014	0.60046	0.00032
27	30	Unbiased	0.60008	0.60013	5e-05
28	30	Biased	0.60044	0.60012	-0.00032
29	30	Unbiased	0.60048	0.6004	-8e-05
30	20	Biased	0.59987	0.59989	2e-05
31	30	Unbiased	0.60042	0.60046	4e-05
33	30	Biased	0.6001	0.60006	-4e-05
34	50	Unbiased	0.60005	0.60036	0.00031
35	20	Unbiased	0.60042	0.60033	-9e-05
41	30	Biased	0.60027	0.60055	0.00028

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.60015	0.60021	0.60037	0.00010677	0.60015	0.60023	0.6004	0.00011701	0	1.75e-05	4e-05	2.0616e-05
20	0.59986	0.60021	0.6005	0.00025114	0.59989	0.60016	0.60048	0.0002233	-0.00059	-5.2e-05	0.00021	0.00020943
30	0.5999	0.6002	0.60049	0.00024482	0.59949	0.6001	0.60055	0.00036496	-0.00041	-0.000105	0.00028	0.00020566
50	0.59972	0.60004	0.60038	0.00021426	0.59947	0.60008	0.60057	0.00042275	-0.00025	3.7e-05	0.00036	0.00024998

Device Test: 19.45 VOLTAGE|OFFSET//12/12/0/0/5/500kHz//@EA_OS





Test Results (Upper Limit = 6.0 (mV))

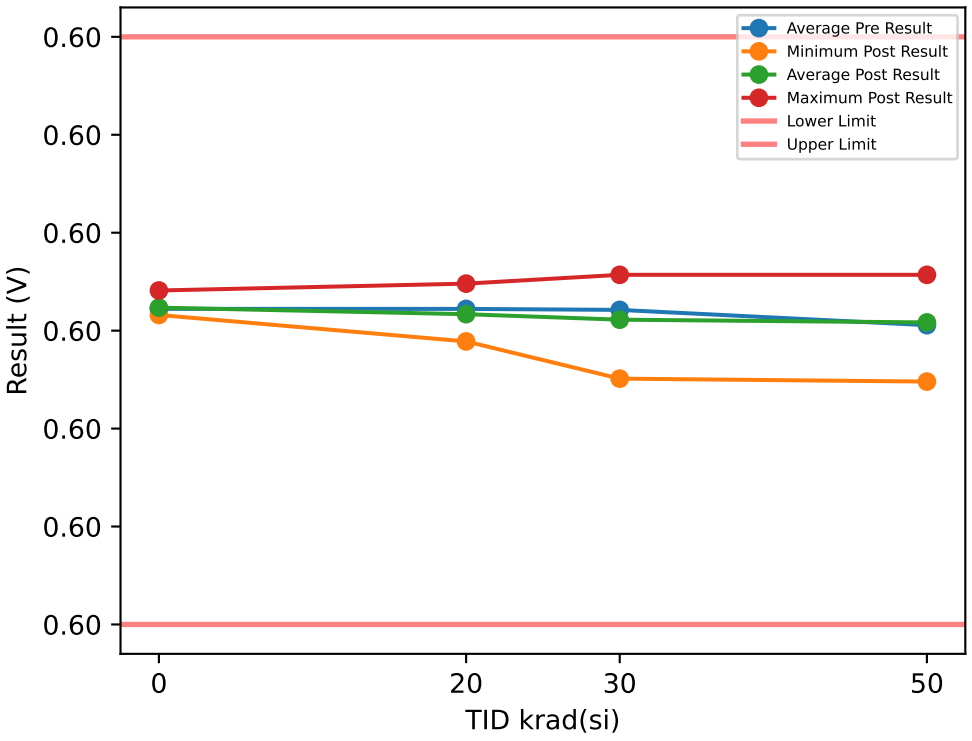
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	1.6398	1.644	0.0042
2	20	Unbiased	0.783	0.7874	0.0044
3	50	Biased	-0.4861	-0.4256	0.0605
4	30	Unbiased	1.3222	1.3328	0.0106
5	50	Unbiased	2.5337	2.5536	0.0199
6	30	Biased	1.3941	1.4101	0.016
7	50	Biased	1.0652	1.1249	0.0597
8	30	Unbiased	1.7772	1.7711	-0.0061
9	20	Unbiased	2.0442	2.075	0.0308
10	50	Biased	1.8309	1.8852	0.0543
11	30	Biased	1.7899	1.8096	0.0197
12	0	Correlation	0.8318	0.8169	-0.0149
13	0	Correlation	0.1354	0.129	-0.0064
14	50	Unbiased	1.9116	1.982	0.0704
15	20	Biased	2.0167	1.9966	-0.0201
16	20	Unbiased	0.1723	0.1334	-0.0389
17	20	Biased	1.6348	1.6092	-0.0256
18	20	Unbiased	0.4219	0.4124	-0.0095
19	20	Biased	1.732	1.7394	0.0074
20	50	Unbiased	0.3446	0.4032	0.0586
21	0	Correlation	1.437	1.4206	-0.0164
22	50	Unbiased	-0.0042	0.0822	0.0864
23	0	Correlation	0.7017	0.6934	-0.0083
24	20	Biased	1.3106	1.2795	-0.0311
26	50	Biased	1.9741	2.0558	0.0817
27	30	Unbiased	1.5446	1.5893	0.0447
28	30	Biased	0.6425	0.6181	-0.0244
29	30	Unbiased	1.0168	0.9919	-0.0249
30	20	Biased	2.9672	2.955	-0.0122
31	30	Unbiased	2.0459	2.0583	0.0124
33	30	Biased	0.8006	0.8085	0.0079
34	50	Unbiased	0.8323	0.9483	0.116
35	20	Unbiased	-0.0756	-0.0482	0.0274
41	30	Biased	2.0411	1.711	-0.3301

Test Statistics (mV)

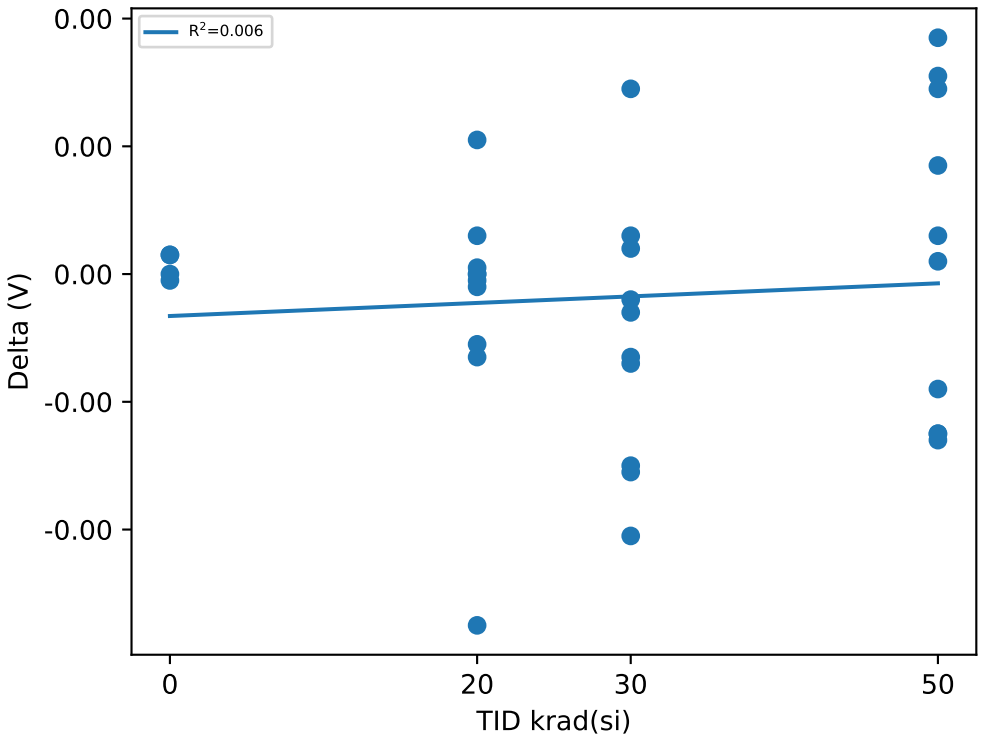
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.1354	0.77648	1.437	0.53414	0.129	0.76497	1.4206	0.52982	-0.0164	-0.0115	-0.0064	0.0048929
20	-0.0756	1.3007	2.9672	0.96311	-0.0482	1.294	2.955	0.9628	-0.0389	-0.00674	0.0308	0.0238
30	0.6425	1.4375	2.0459	0.49614	0.6181	1.4101	2.0583	0.47173	-0.3301	-0.02742	0.0447	0.10836
50	-0.4861	1.1642	2.5337	0.97986	-0.4256	1.2254	2.5536	0.96795	0.0042	0.06117	0.116	0.031894

Device Test: 19.46 VOLTAGE|VREF//14/14/0/0/5/500kHz//@VREF_25C

TID vs Result Stats



TID vs Post - Pre Exposure Delta



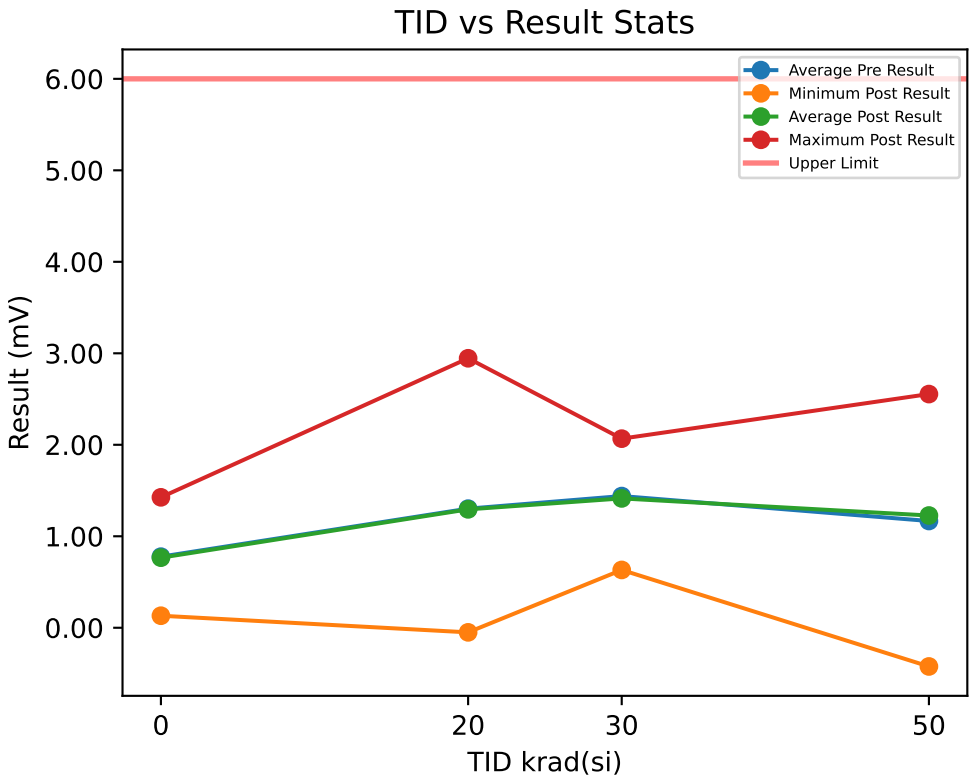
Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

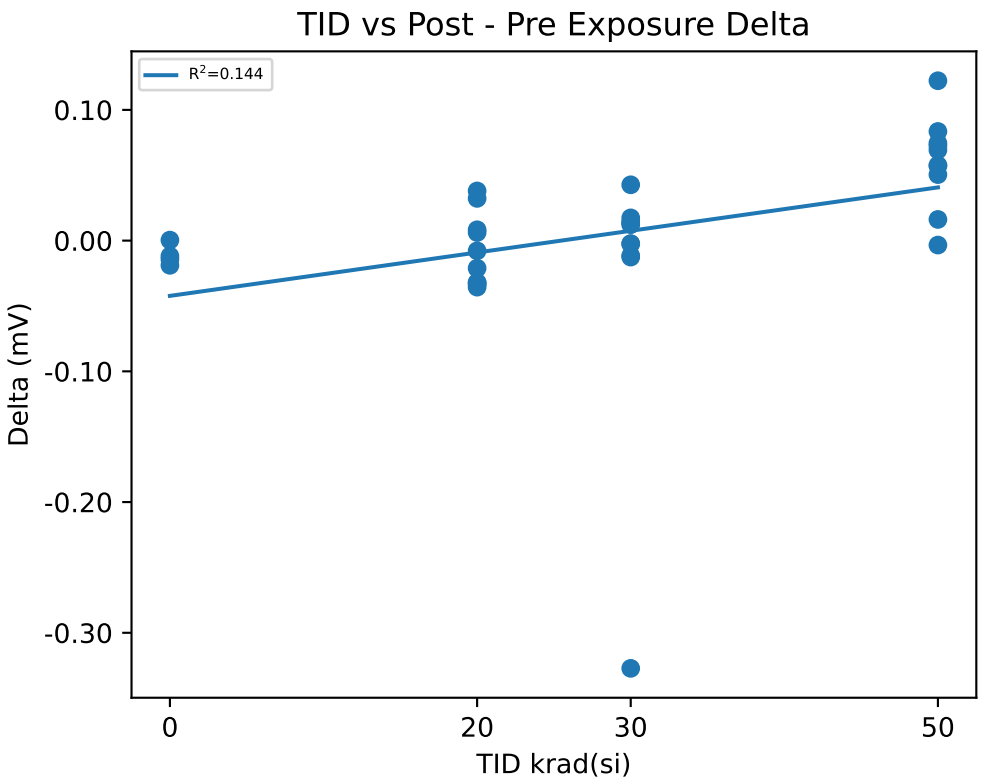
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	0.60012	0.60018	6e-05
2	20	Unbiased	0.60043	0.60042	-1e-05
3	50	Biased	0.59973	0.59948	-0.00025
4	30	Unbiased	0.59996	0.59982	-0.00014
5	50	Unbiased	0.6003	0.60032	2e-05
6	30	Biased	0.59992	0.59962	-0.0003
7	50	Biased	0.59998	0.59972	-0.00026
8	30	Unbiased	0.59992	0.59951	-0.00041
9	20	Unbiased	0.59988	0.60009	0.00021
10	50	Biased	0.59974	0.59949	-0.00025
11	30	Biased	0.6005	0.60037	-0.00013
12	0	Correlation	0.60017	0.60016	-1e-05
13	0	Correlation	0.60038	0.60041	3e-05
14	50	Unbiased	0.59997	0.59979	-0.00018
15	20	Biased	0.60007	0.59994	-0.00013
16	20	Unbiased	0.60017	0.60017	0
17	20	Biased	0.60002	0.60008	6e-05
18	20	Unbiased	0.60048	0.59993	-0.00055
19	20	Biased	0.60038	0.60036	-2e-05
20	50	Unbiased	0.6004	0.60057	0.00017
21	0	Correlation	0.60018	0.60021	3e-05
22	50	Unbiased	0.6001	0.60047	0.00037
23	0	Correlation	0.60016	0.60016	0
24	20	Biased	0.60047	0.60048	1e-05
26	50	Biased	0.60016	0.60045	0.00029
27	30	Unbiased	0.60008	0.60014	6e-05
28	30	Biased	0.60045	0.60014	-0.00031
29	30	Unbiased	0.60047	0.60041	-6e-05
30	20	Biased	0.59989	0.59989	0
31	30	Unbiased	0.60043	0.60047	4e-05
33	30	Biased	0.60011	0.60007	-4e-05
34	50	Unbiased	0.60006	0.60037	0.00031
35	20	Unbiased	0.60043	0.60032	-0.00011
41	30	Biased	0.60028	0.60057	0.00029

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.60016	0.60022	0.60038	0.00010532	0.60016	0.60024	0.60041	0.00011902	-1e-05	1.25e-05	3e-05	2.0616e-05
20	0.59988	0.60022	0.60048	0.00024344	0.59989	0.60017	0.60048	0.00021617	-0.00055	-5.4e-05	0.00021	0.00019738
30	0.59992	0.60021	0.6005	0.00024041	0.59951	0.60011	0.60057	0.00036307	-0.00041	-0.0001	0.00029	0.00020688
50	0.59973	0.60006	0.6004	0.00021449	0.59948	0.60008	0.60057	0.00042196	-0.00026	2.8e-05	0.00037	0.00025103

Device Test: 19.48 VOLTAGE|OFFSET//14/14/0/0/5/500kHz//@EA_OS





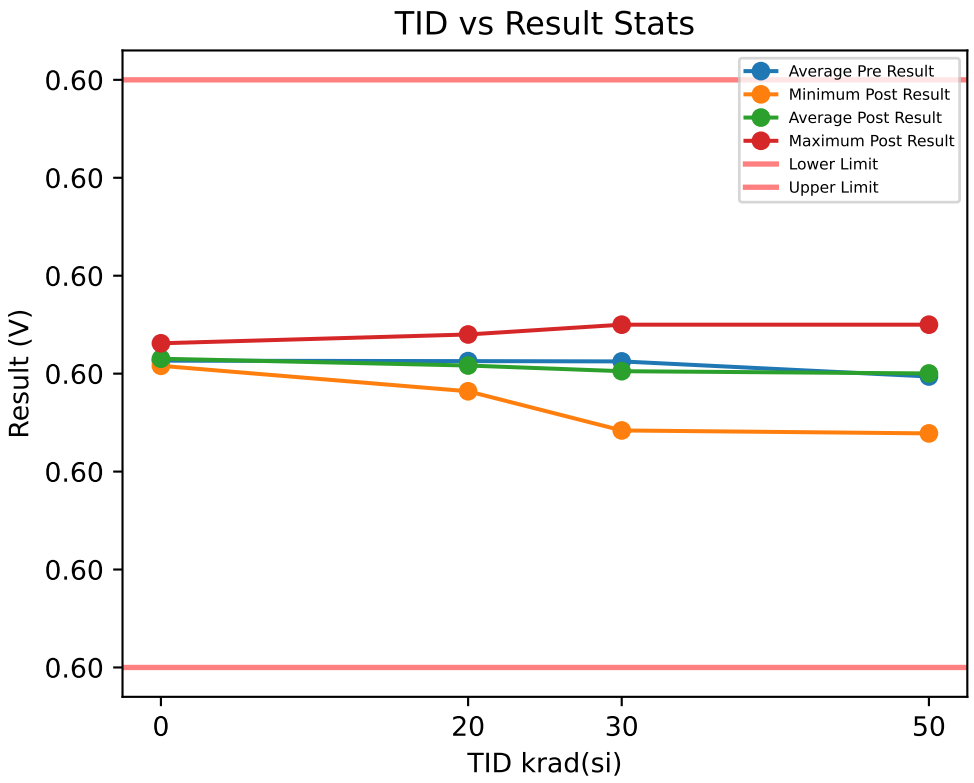
Test Results (Upper Limit = 6.0 (mV))

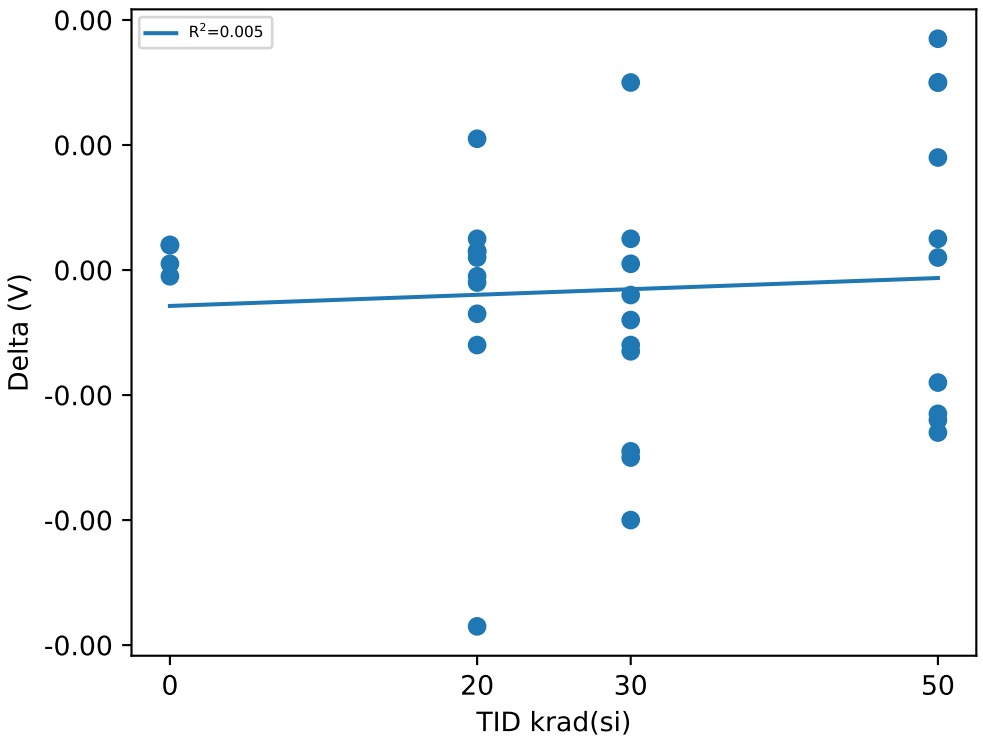
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	1.6444	1.641	-0.0034
2	20	Unbiased	0.7722	0.7805	0.0083
3	50	Biased	-0.4923	-0.423	0.0693
4	30	Unbiased	1.3342	1.3227	-0.0115
5	50	Unbiased	2.5381	2.5543	0.0162
6	30	Biased	1.3988	1.411	0.0122
7	50	Biased	1.0692	1.1264	0.0572
8	30	Unbiased	1.7773	1.7749	-0.0024
9	20	Unbiased	2.0451	2.0831	0.038
10	50	Biased	1.8314	1.8891	0.0577
11	30	Biased	1.7928	1.8102	0.0174
12	0	Correlation	0.8257	0.8068	-0.0189
13	0	Correlation	0.1311	0.1315	0.0004
14	50	Unbiased	1.9108	1.9834	0.0726
15	20	Biased	2.0219	2.0008	-0.0211
16	20	Unbiased	0.1772	0.1416	-0.0356
17	20	Biased	1.6448	1.6126	-0.0322
18	20	Unbiased	0.4149	0.4211	0.0062
19	20	Biased	1.7389	1.7311	-0.0078
20	50	Unbiased	0.3496	0.4001	0.0505
21	0	Correlation	1.44	1.4257	-0.0143
22	50	Unbiased	0.0043	0.0878	0.0835
23	0	Correlation	0.7116	0.6998	-0.0118
24	20	Biased	1.3082	1.2762	-0.032
26	50	Biased	1.9836	2.0582	0.0746
27	30	Unbiased	1.5425	1.5852	0.0427
28	30	Biased	0.6344	0.632	-0.0024
29	30	Unbiased	1.0112	0.9986	-0.0126
30	20	Biased	2.9791	2.9456	-0.0335
31	30	Unbiased	2.0535	2.067	0.0135
33	30	Biased	0.7969	0.811	0.0141
34	50	Unbiased	0.8301	0.9524	0.1223
35	20	Unbiased	-0.0825	-0.0502	0.0323
41	30	Biased	2.0526	1.7254	-0.3272

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.1311	0.7771	1.44	0.53647	0.1315	0.76595	1.4257	0.53036	-0.0189	-0.01115	0.0004	0.0082424
20	-0.0825	1.302	2.9791	0.96846	-0.0502	1.2942	2.9456	0.96052	-0.0356	-0.00774	0.038	0.027793
30	0.6344	1.4394	2.0535	0.50108	0.632	1.4138	2.067	0.47093	-0.3272	-0.02562	0.0427	0.10721
50	-0.4923	1.1669	2.5381	0.98125	-0.423	1.227	2.5543	0.96748	-0.0034	0.06005	0.1223	0.034854

Device Test: 19.49 VOLTAGE|VREF//4.5/4.5/0/0/4.5/1MHz//@VREF_25C





Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

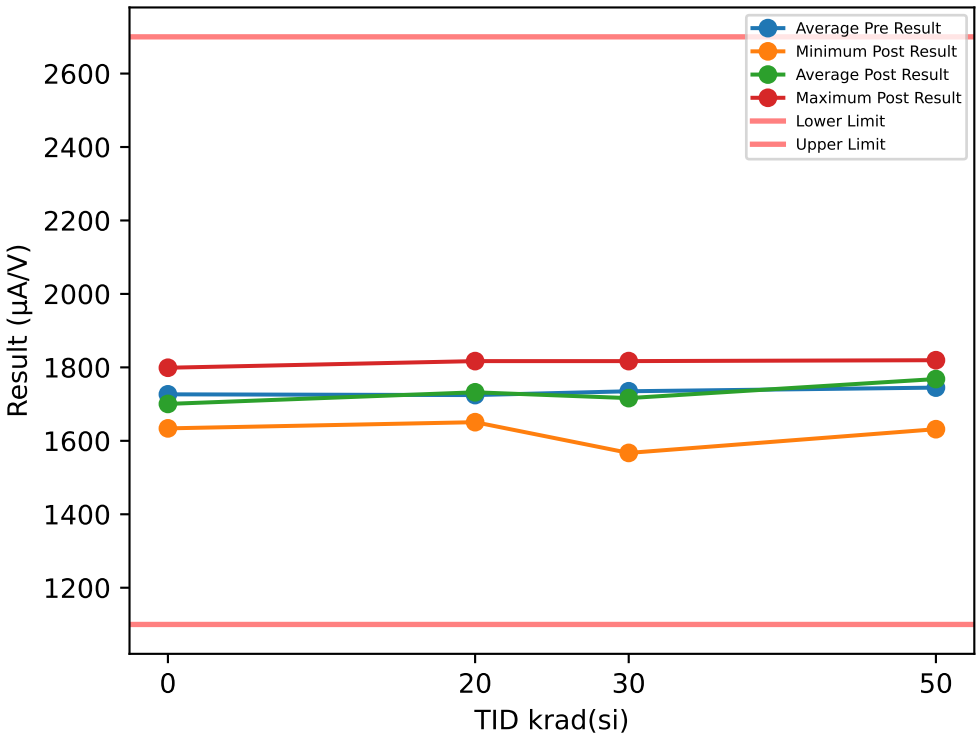
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	0.60004	0.60009	5e-05
2	20	Unbiased	0.60033	0.60035	2e-05
3	50	Biased	0.59965	0.59939	-0.00026
4	30	Unbiased	0.59986	0.59974	-0.00012
5	50	Unbiased	0.60022	0.60024	2e-05
6	30	Biased	0.59983	0.59954	-0.00029
7	50	Biased	0.59988	0.59964	-0.00024
8	30	Unbiased	0.59982	0.59942	-0.0004
9	20	Unbiased	0.59979	0.6	0.00021
10	50	Biased	0.59965	0.59942	-0.00023
11	30	Biased	0.60041	0.60028	-0.00013
12	0	Correlation	0.60008	0.60009	1e-05
13	0	Correlation	0.60027	0.60031	4e-05
14	50	Unbiased	0.5999	0.59972	-0.00018
15	20	Biased	0.59999	0.59987	-0.00012
16	20	Unbiased	0.60008	0.60007	-1e-05
17	20	Biased	0.59993	0.59998	5e-05
18	20	Unbiased	0.60039	0.59982	-0.00057
19	20	Biased	0.6003	0.60028	-2e-05
20	50	Unbiased	0.60032	0.6005	0.00018
21	0	Correlation	0.60009	0.60013	4e-05
22	50	Unbiased	0.60001	0.60038	0.00037
23	0	Correlation	0.60009	0.60008	-1e-05
24	20	Biased	0.60037	0.6004	3e-05
26	50	Biased	0.60007	0.60037	0.0003
27	30	Unbiased	0.6	0.60005	5e-05
28	30	Biased	0.60034	0.60004	-0.0003
29	30	Unbiased	0.60039	0.60031	-8e-05
30	20	Biased	0.59979	0.59982	3e-05
31	30	Unbiased	0.60037	0.60038	1e-05
33	30	Biased	0.60003	0.59999	-4e-05
34	50	Unbiased	0.59997	0.60027	0.0003
35	20	Unbiased	0.60031	0.60024	-7e-05
41	30	Biased	0.6002	0.6005	0.0003

Test Statistics (V)

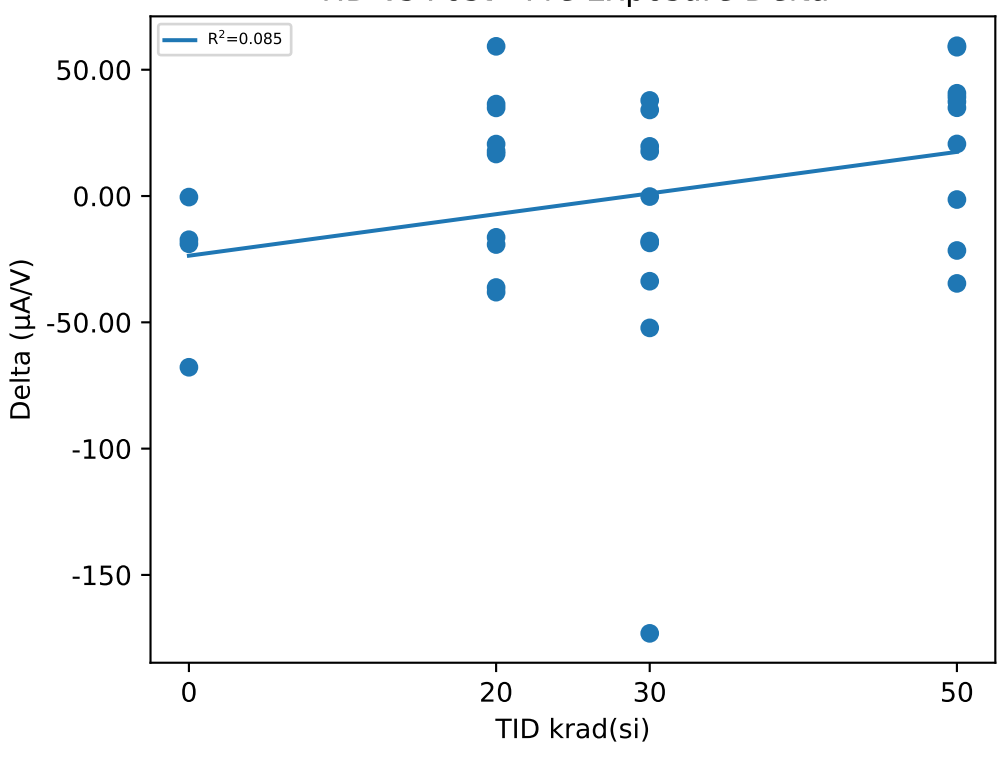
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.60008	0.60013	0.60027	9.1788e-05	0.60008	0.60015	0.60031	0.0001072	-1e-05	2e-05	4e-05	2.4495e-05
20	0.59979	0.60013	0.60039	0.00024031	0.59982	0.60008	0.6004	0.00022025	-0.00057	-4.5e-05	0.00021	0.00020365
30	0.59982	0.60013	0.60041	0.00024455	0.59942	0.60003	0.6005	0.00036247	-0.0004	-0.0001	0.0003	0.00020166
50	0.59965	0.59997	0.60032	0.00021584	0.59939	0.6	0.6005	0.00041984	-0.00026	3.1e-05	0.00037	0.0002479

Device Test: 19.5 LEVEL|TRANSCONDUCTANCE//5/5/0/0/5/500kHz//@EA_GM

TID vs Result Stats



TID vs Post - Pre Exposure Delta



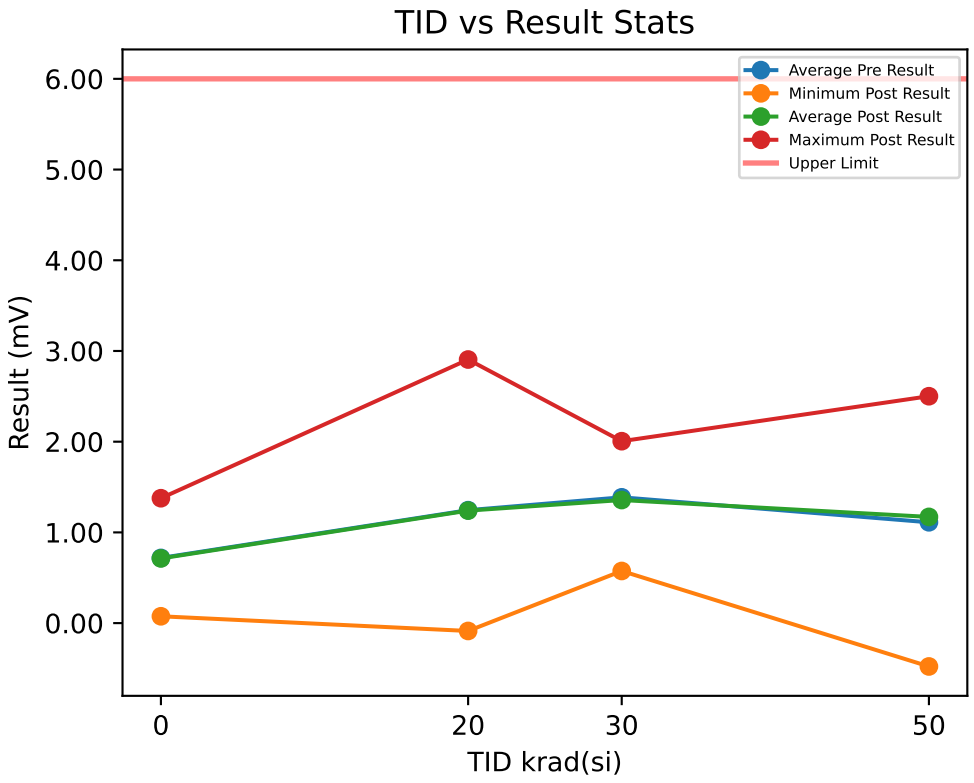
Test Results (Lower Limit = 1100.0, Upper Limit = 2700.0 (µA/V))

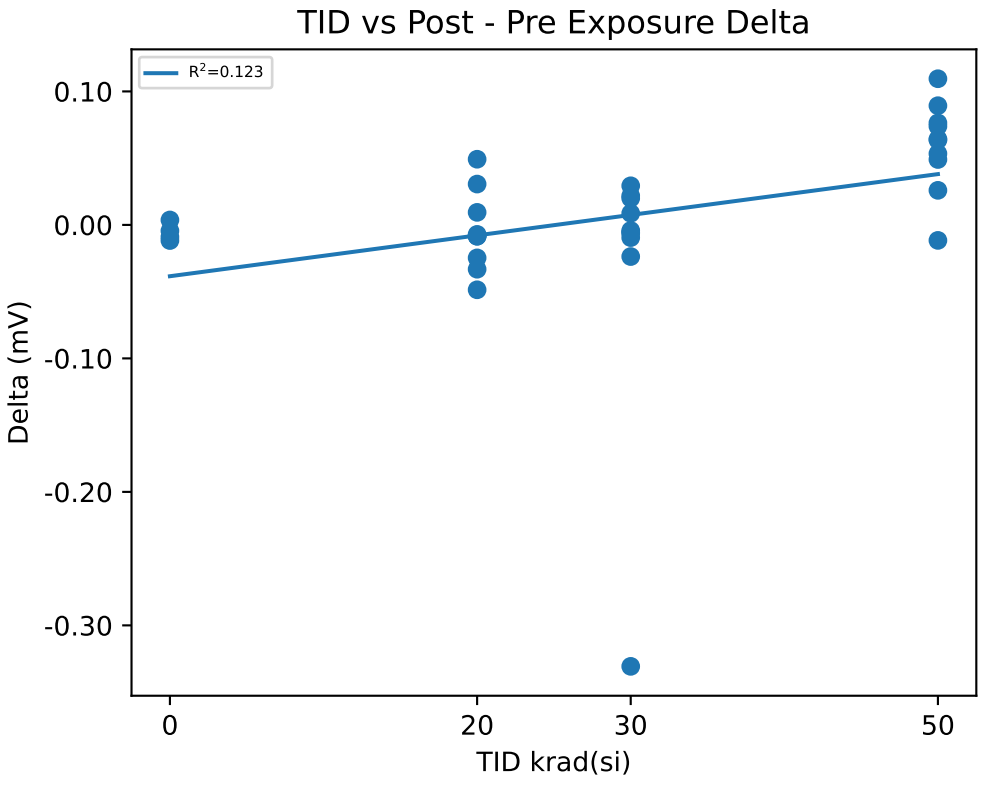
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	1720.8	1719.4	-1.3844
2	20	Unbiased	1778.8	1796.6	17.83
3	50	Biased	1666.2	1631.7	-34.589
4	30	Unbiased	1779.4	1799	19.663
5	50	Unbiased	1739.5	1799	59.499
6	30	Biased	1740.1	1721.6	-18.553
7	50	Biased	1838.6	1817.1	-21.556
8	30	Unbiased	1722	1721.8	-0.212
9	20	Unbiased	1633	1667.9	34.894
10	50	Biased	1798.8	1819.4	20.619
11	30	Biased	1720	1667.8	-52.2
12	0	Correlation	1799.4	1799	-0.4149
13	0	Correlation	1684.5	1665.6	-18.898
14	50	Unbiased	1778.8	1819.5	40.685
15	20	Biased	1757.8	1721.6	-36.21
16	20	Unbiased	1634.1	1650.8	16.633
17	20	Biased	1758.6	1779.2	20.57
18	20	Unbiased	1778.8	1759.6	-19.207
19	20	Biased	1757.8	1817.1	59.265
20	50	Unbiased	1759.8	1799	39.214
21	0	Correlation	1720.8	1703.5	-17.297
22	50	Unbiased	1740.1	1799	58.909
23	0	Correlation	1701.7	1633.9	-67.79
24	20	Biased	1759.8	1721.8	-38.062
26	50	Biased	1703.1	1740.5	37.36
27	30	Unbiased	1777.3	1759.5	-17.819
28	30	Biased	1799.4	1817.1	17.676
29	30	Unbiased	1667	1701.1	34.083
30	20	Biased	1685.2	1721.6	36.401
31	30	Unbiased	1701.7	1668	-33.726
33	30	Biased	1702.4	1740.3	37.853
34	50	Unbiased	1703.1	1738.1	34.952
35	20	Unbiased	1701.7	1685.3	-16.342
41	30	Biased	1740.2	1567.1	-173.13

Test Statistics (µA/V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1684.5	1726.6	1799.4	50.733	1633.9	1700.5	1799	71.543	-67.79	-26.1	-0.4149	29.024
20	1633	1724.6	1778.8	56.899	1650.8	1732.1	1817.1	55.388	-38.062	7.5772	59.265	33.157
30	1667	1735	1799.4	41.027	1567.1	1716.3	1817.1	72.029	-173.13	-18.637	37.853	61.751
50	1666.2	1744.9	1838.6	50.96	1631.7	1768.3	1819.5	60.733	-34.589	23.371	59.499	32.399

Device Test: 19.51 VOLTAGE|OFFSET//4.5/4.5/0/0/4.5/1MHz//@EA_OS





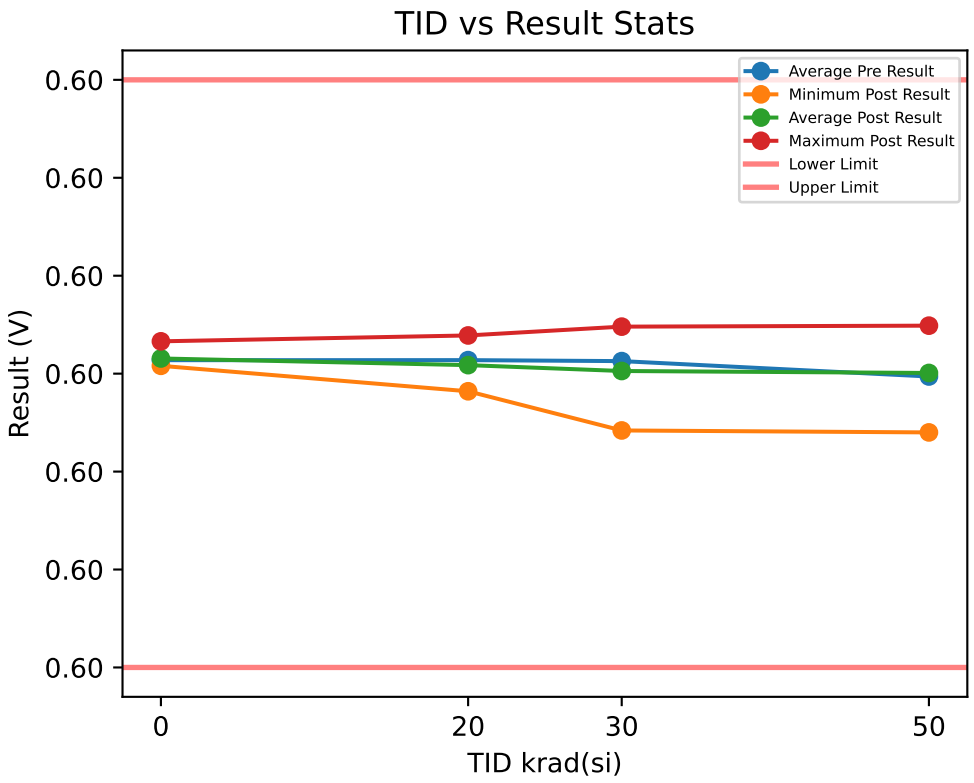
Test Results (Upper Limit = 6.0 (mV))

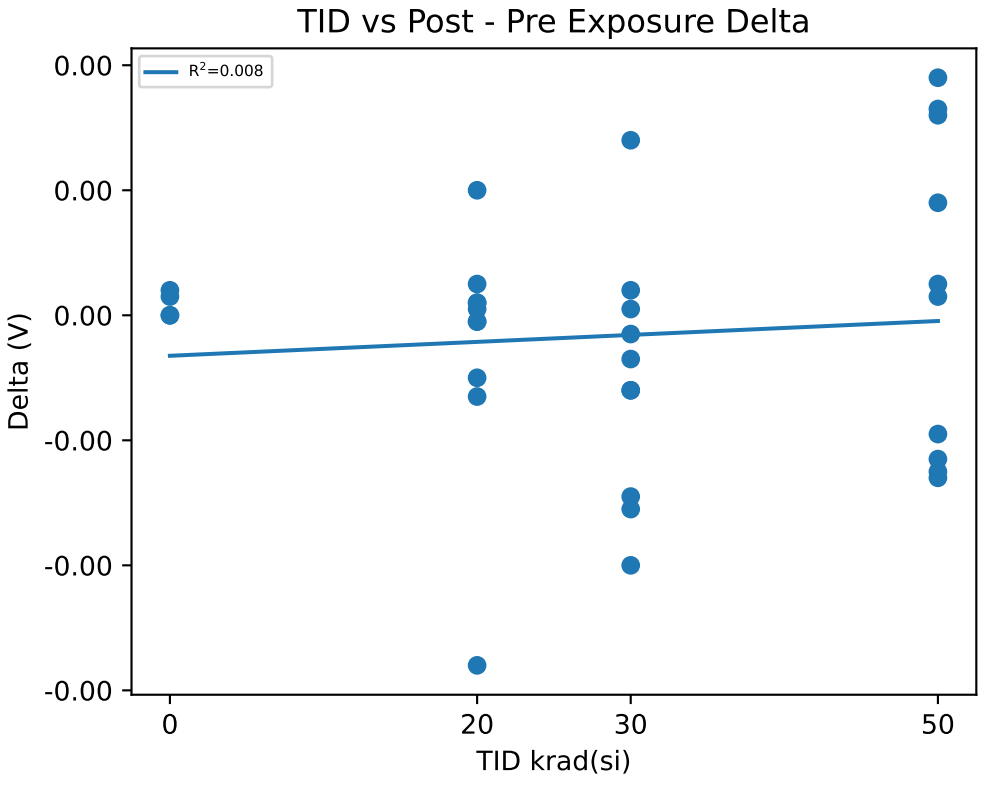
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	1.5904	1.5788	-0.0116
2	20	Unbiased	0.7224	0.7318	0.0094
3	50	Biased	-0.5268	-0.4778	0.049
4	30	Unbiased	1.2772	1.271	-0.0062
5	50	Unbiased	2.4753	2.5012	0.0259
6	30	Biased	1.3411	1.3611	0.02
7	50	Biased	1.0097	1.0836	0.0739
8	30	Unbiased	1.7247	1.7152	-0.0095
9	20	Unbiased	1.9889	2.0195	0.0306
10	50	Biased	1.768	1.8323	0.0643
11	30	Biased	1.7403	1.7621	0.0218
12	0	Correlation	0.7729	0.7612	-0.0117
13	0	Correlation	0.0716	0.0753	0.0037
14	50	Unbiased	1.8479	1.9243	0.0764
15	20	Biased	1.9602	1.9531	-0.0071
16	20	Unbiased	0.1219	0.0733	-0.0486
17	20	Biased	1.5843	1.5511	-0.0332
18	20	Unbiased	0.3667	0.3582	-0.0085
19	20	Biased	1.6838	1.6757	-0.0081
20	50	Unbiased	0.2914	0.3448	0.0534
21	0	Correlation	1.3812	1.3768	-0.0044
22	50	Unbiased	-0.0559	0.0334	0.0893
23	0	Correlation	0.6483	0.6393	-0.009
24	20	Biased	1.2437	1.219	-0.0247
26	50	Biased	1.934	1.9976	0.0636
27	30	Unbiased	1.4947	1.524	0.0293
28	30	Biased	0.5789	0.5747	-0.0042
29	30	Unbiased	0.9576	0.9339	-0.0237
30	20	Biased	2.9142	2.9058	-0.0084
31	30	Unbiased	2.011	2.0055	-0.0055
33	30	Biased	0.7487	0.7574	0.0087
34	50	Unbiased	0.7811	0.8906	0.1095
35	20	Unbiased	-0.1357	-0.0865	0.0492
41	30	Biased	1.9933	1.6626	-0.3307

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.0716	0.7185	1.3812	0.53713	0.0753	0.71315	1.3768	0.53387	-0.0117	-0.00535	0.0037	0.0067441
20	-0.1357	1.245	2.9142	0.96442	-0.0865	1.2401	2.9058	0.96233	-0.0486	-0.00494	0.0492	0.028934
30	0.5789	1.3867	2.011	0.50182	0.5747	1.3567	2.0055	0.47048	-0.3307	-0.03	0.0293	0.10693
50	-0.5268	1.1115	2.4753	0.97628	-0.4778	1.1709	2.5012	0.9664	-0.0116	0.05937	0.1095	0.033751

Device Test: 19.52 VOLTAGE|VREF//5/5/0/0/5/1MHz//@VREF_25C





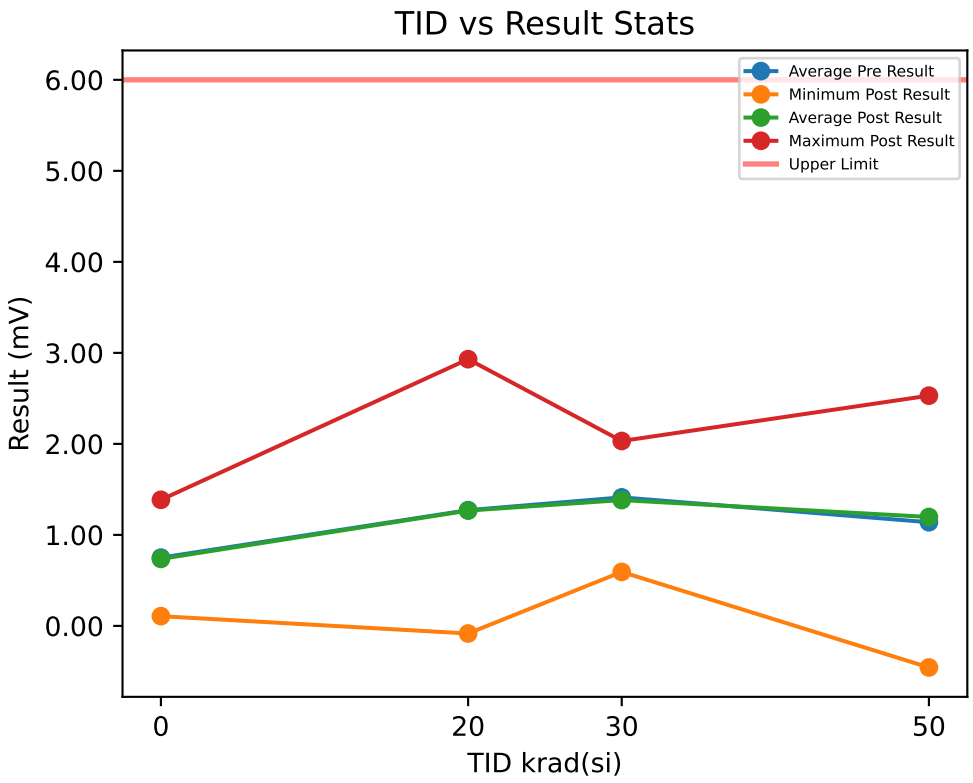
Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

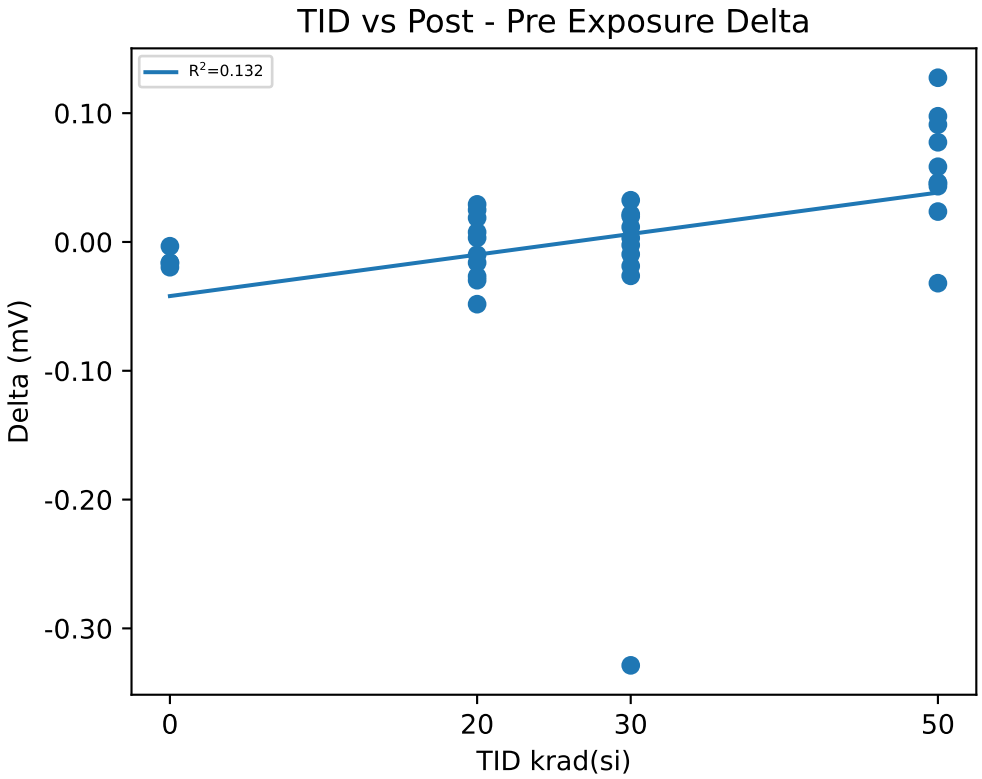
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	0.60005	0.6001	5e-05
2	20	Unbiased	0.60035	0.60036	1e-05
3	50	Biased	0.59966	0.5994	-0.00026
4	30	Unbiased	0.59985	0.59973	-0.00012
5	50	Unbiased	0.60022	0.60025	3e-05
6	30	Biased	0.59983	0.59954	-0.00029
7	50	Biased	0.5999	0.59965	-0.00025
8	30	Unbiased	0.59982	0.59942	-0.0004
9	20	Unbiased	0.5998	0.6	0.0002
10	50	Biased	0.59965	0.59942	-0.00023
11	30	Biased	0.60041	0.60029	-0.00012
12	0	Correlation	0.60009	0.60009	0
13	0	Correlation	0.60029	0.60033	4e-05
14	50	Unbiased	0.59989	0.5997	-0.00019
15	20	Biased	0.59999	0.59986	-0.00013
16	20	Unbiased	0.60009	0.60008	-1e-05
17	20	Biased	0.59994	0.59999	5e-05
18	20	Unbiased	0.6004	0.59984	-0.00056
19	20	Biased	0.6003	0.60029	-1e-05
20	50	Unbiased	0.60031	0.60049	0.00018
21	0	Correlation	0.60009	0.60012	3e-05
22	50	Unbiased	0.60001	0.60039	0.00038
23	0	Correlation	0.60008	0.60008	0
24	20	Biased	0.60037	0.60039	2e-05
26	50	Biased	0.60005	0.60037	0.00032
27	30	Unbiased	0.60001	0.60005	4e-05
28	30	Biased	0.60036	0.60005	-0.00031
29	30	Unbiased	0.6004	0.60033	-7e-05
30	20	Biased	0.5998	0.59982	2e-05
31	30	Unbiased	0.60037	0.60038	1e-05
33	30	Biased	0.60003	0.6	-3e-05
34	50	Unbiased	0.59997	0.6003	0.00033
35	20	Unbiased	0.60034	0.60024	-0.0001
41	30	Biased	0.6002	0.60048	0.00028

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.60008	0.60014	0.60029	0.00010178	0.60008	0.60015	0.60033	0.0001179	0	1.75e-05	4e-05	2.0616e-05
20	0.5998	0.60014	0.6004	0.00024184	0.59982	0.60009	0.60039	0.00021904	-0.00056	-5.1e-05	0.0002	0.00019947
30	0.59982	0.60013	0.60041	0.00024845	0.59942	0.60003	0.60048	0.00036307	-0.0004	-0.000101	0.00028	0.00019802
50	0.59965	0.59997	0.60031	0.00021142	0.5994	0.60001	0.60049	0.00042164	-0.00026	3.6e-05	0.00038	0.00025769

Device Test: 19.54 VOLTAGE|OFFSET//5/5/0/0/5/1MHz//@EA_OS





Test Results (Upper Limit = 6.0 (mV))

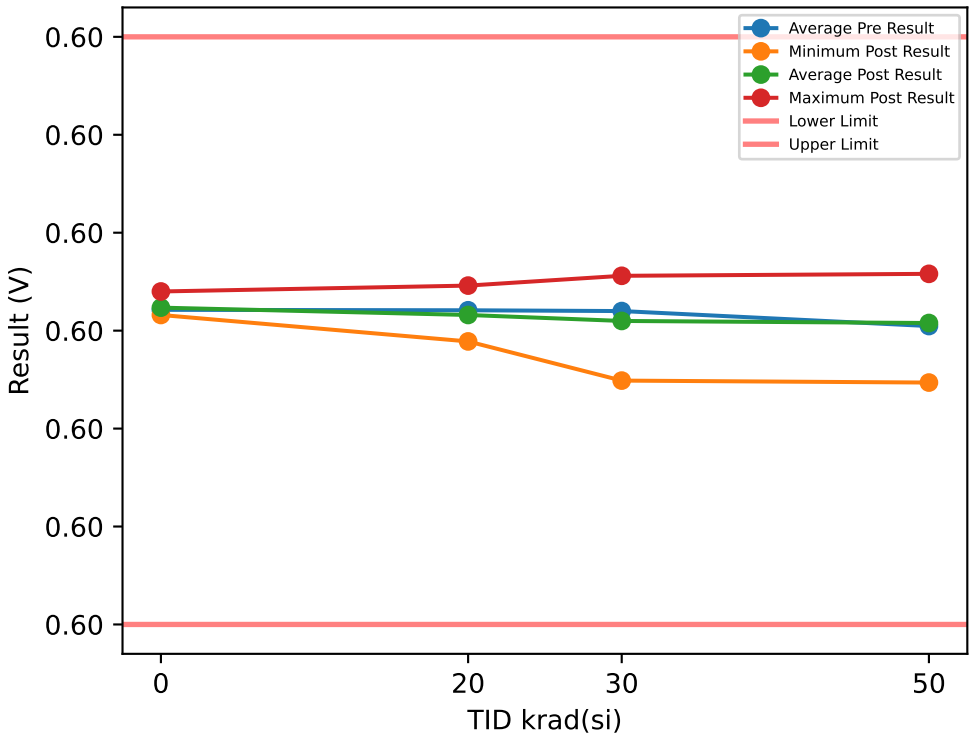
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	1.6355	1.6035	-0.032
2	20	Unbiased	0.7407	0.7699	0.0292
3	50	Biased	-0.5026	-0.4566	0.046
4	30	Unbiased	1.3044	1.302	-0.0024
5	50	Unbiased	2.5063	2.5299	0.0236
6	30	Biased	1.3681	1.388	0.0199
7	50	Biased	1.051	1.0943	0.0433
8	30	Unbiased	1.7453	1.7357	-0.0096
9	20	Unbiased	2.0213	2.0462	0.0249
10	50	Biased	1.8014	1.8598	0.0584
11	30	Biased	1.7664	1.7879	0.0215
12	0	Correlation	0.8064	0.7903	-0.0161
13	0	Correlation	0.1103	0.107	-0.0033
14	50	Unbiased	1.8714	1.9488	0.0774
15	20	Biased	1.9924	1.9763	-0.0161
16	20	Unbiased	0.149	0.1007	-0.0483
17	20	Biased	1.6129	1.5862	-0.0267
18	20	Unbiased	0.3844	0.392	0.0076
19	20	Biased	1.7047	1.7079	0.0032
20	50	Unbiased	0.3185	0.364	0.0455
21	0	Correlation	1.4017	1.3854	-0.0163
22	50	Unbiased	-0.0343	0.0568	0.0911
23	0	Correlation	0.6816	0.662	-0.0196
24	20	Biased	1.274	1.2443	-0.0297
26	50	Biased	1.9434	2.041	0.0976
27	30	Unbiased	1.5164	1.5488	0.0324
28	30	Biased	0.612	0.5933	-0.0187
29	30	Unbiased	0.9893	0.963	-0.0263
30	20	Biased	2.9406	2.9307	-0.0099
31	30	Unbiased	2.0286	2.0317	0.0031
33	30	Biased	0.772	0.7836	0.0116
34	50	Unbiased	0.7999	0.9274	0.1275
35	20	Unbiased	-0.1021	-0.0834	0.0187
41	30	Biased	2.0199	1.6912	-0.3287

Test Statistics (mV)

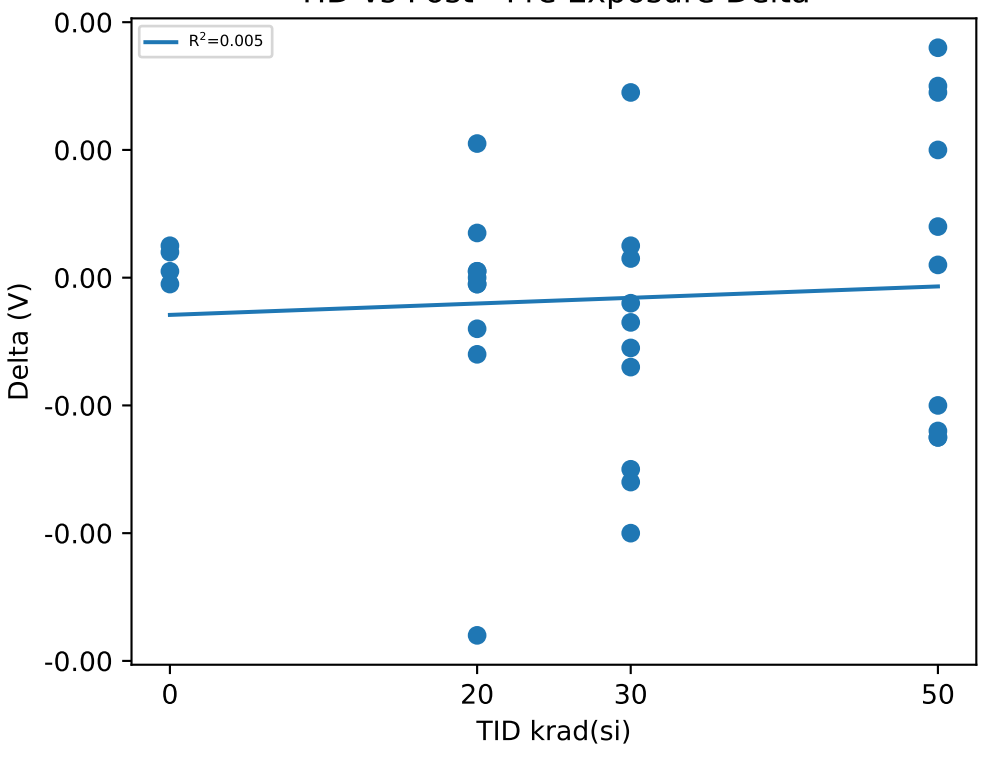
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.1103	0.75	1.4017	0.52971	0.107	0.73618	1.3854	0.52465	-0.0196	-0.013825	-0.0033	0.0071979
20	-0.1021	1.2718	2.9406	0.96537	-0.0834	1.2671	2.9307	0.96445	-0.0483	-0.00471	0.0292	0.02572
30	0.612	1.4122	2.0286	0.49879	0.5933	1.3825	2.0317	0.47111	-0.3287	-0.02972	0.0324	0.10667
50	-0.5026	1.139	2.5063	0.97785	-0.4566	1.1969	2.5299	0.97012	-0.032	0.05784	0.1275	0.044309

Device Test: 19.55 VOLTAGE|VREF//12/12/0/0/5/1MHz//@VREF_25C

TID vs Result Stats



TID vs Post - Pre Exposure Delta



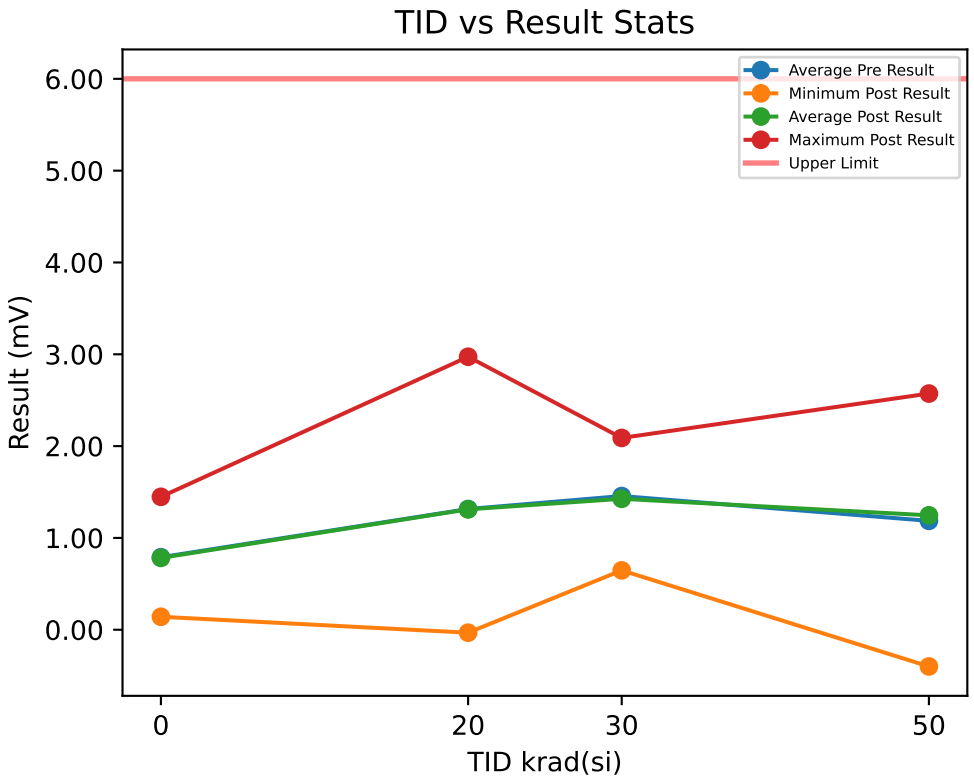
Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

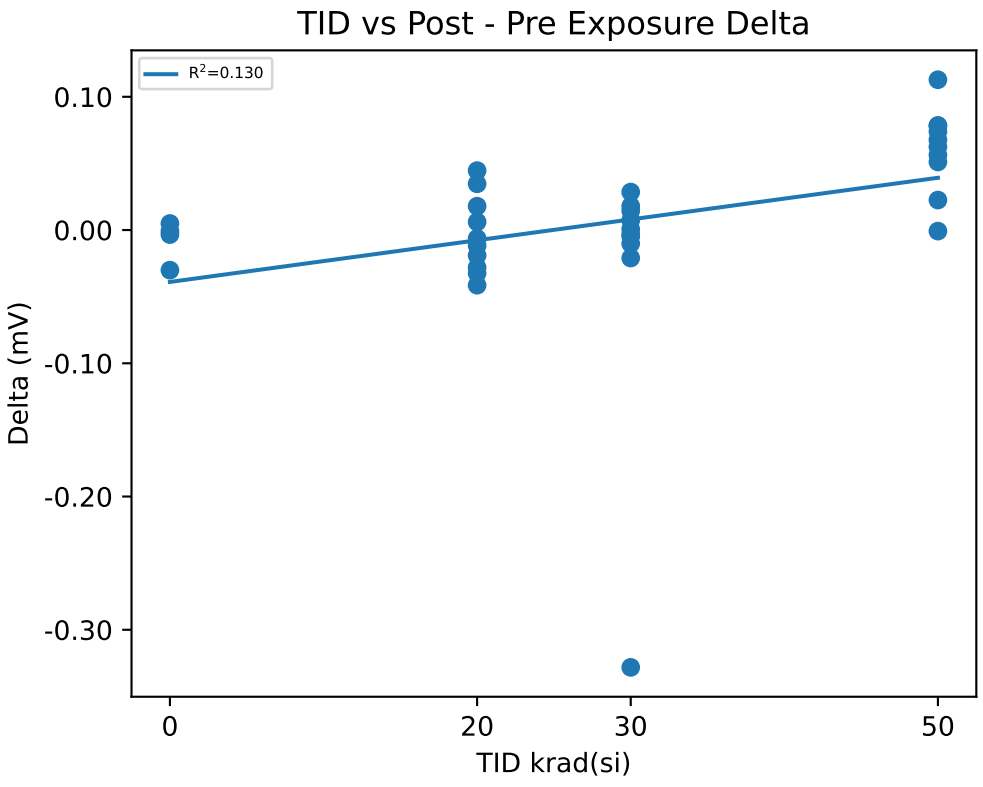
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	0.60009	0.60017	8e-05
2	20	Unbiased	0.60043	0.60043	0
3	50	Biased	0.59972	0.59947	-0.00025
4	30	Unbiased	0.59993	0.59982	-0.00011
5	50	Unbiased	0.60029	0.60031	2e-05
6	30	Biased	0.59991	0.59959	-0.00032
7	50	Biased	0.59997	0.59972	-0.00025
8	30	Unbiased	0.59989	0.59949	-0.0004
9	20	Unbiased	0.59987	0.60008	0.00021
10	50	Biased	0.59973	0.59949	-0.00024
11	30	Biased	0.60049	0.60035	-0.00014
12	0	Correlation	0.60017	0.60016	-1e-05
13	0	Correlation	0.60036	0.6004	4e-05
14	50	Unbiased	0.59998	0.59978	-0.0002
15	20	Biased	0.60005	0.59993	-0.00012
16	20	Unbiased	0.60016	0.60015	-1e-05
17	20	Biased	0.6	0.60007	7e-05
18	20	Unbiased	0.60048	0.59992	-0.00056
19	20	Biased	0.60036	0.60035	-1e-05
20	50	Unbiased	0.60038	0.60058	0.0002
21	0	Correlation	0.60017	0.60022	5e-05
22	50	Unbiased	0.6001	0.60046	0.00036
23	0	Correlation	0.60015	0.60016	1e-05
24	20	Biased	0.60045	0.60046	1e-05
26	50	Biased	0.60015	0.60044	0.00029
27	30	Unbiased	0.60008	0.60013	5e-05
28	30	Biased	0.60044	0.60014	-0.0003
29	30	Unbiased	0.60046	0.60039	-7e-05
30	20	Biased	0.59988	0.59989	1e-05
31	30	Unbiased	0.60043	0.60046	3e-05
33	30	Biased	0.6001	0.60006	-4e-05
34	50	Unbiased	0.60006	0.60036	0.0003
35	20	Unbiased	0.6004	0.60032	-8e-05
41	30	Biased	0.60027	0.60056	0.00029

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.60015	0.60021	0.60036	9.8784e-05	0.60016	0.60024	0.6004	0.00011358	-1e-05	2.25e-05	5e-05	2.7538e-05
20	0.59987	0.60021	0.60048	0.00024362	0.59989	0.60016	0.60046	0.00021669	-0.00056	-4.8e-05	0.00021	0.00020021
30	0.59989	0.6002	0.60049	0.00024599	0.59949	0.6001	0.60056	0.00036553	-0.0004	-0.000101	0.00029	0.00020442
50	0.59972	0.60005	0.60038	0.00021166	0.59947	0.60008	0.60058	0.00042205	-0.00025	3.1e-05	0.00036	0.00025022

Device Test: 19.57 VOLTAGE|OFFSET//12/12/0/0/5/1MHz//@EA_OS





Test Results (Upper Limit = 6.0 (mV))

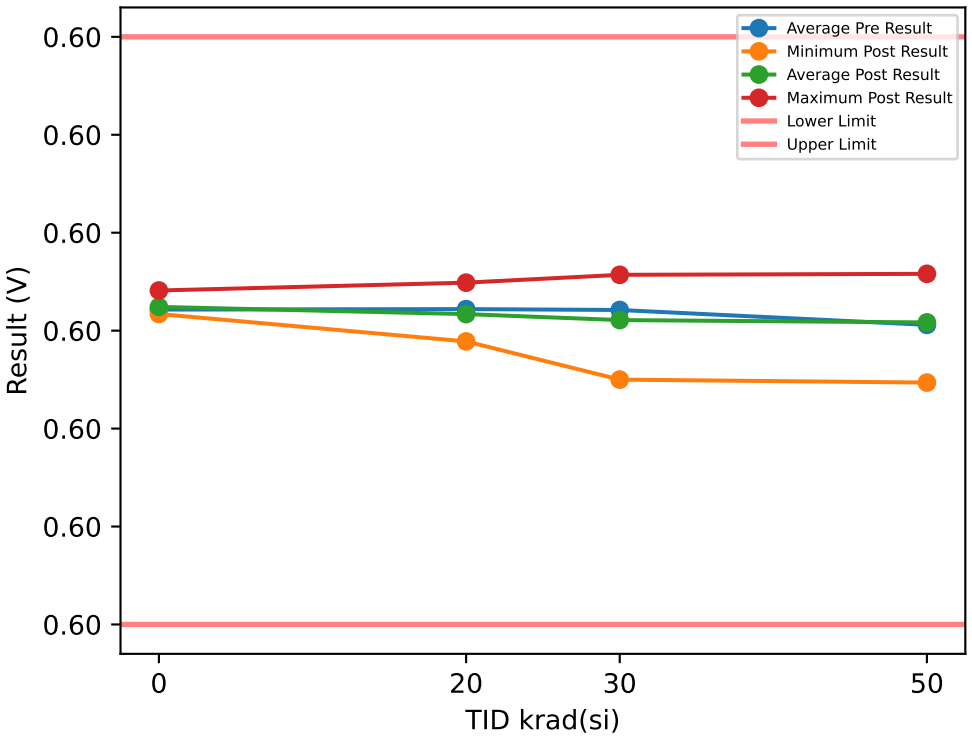
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	1.6518	1.651	-0.0008
2	20	Unbiased	0.7911	0.809	0.0179
3	50	Biased	-0.478	-0.3998	0.0782
4	30	Unbiased	1.3482	1.3489	0.0007
5	50	Unbiased	2.5498	2.5723	0.0225
6	30	Biased	1.4189	1.4087	-0.0102
7	50	Biased	1.0955	1.1466	0.0511
8	30	Unbiased	1.7873	1.7825	-0.0048
9	20	Unbiased	2.0584	2.103	0.0446
10	50	Biased	1.8522	1.9085	0.0563
11	30	Biased	1.8145	1.8218	0.0073
12	0	Correlation	0.8529	0.8228	-0.0301
13	0	Correlation	0.142	0.1413	-0.0007
14	50	Unbiased	1.9401	2.0078	0.0677
15	20	Biased	2.0284	2.0167	-0.0117
16	20	Unbiased	0.187	0.1456	-0.0414
17	20	Biased	1.6471	1.6281	-0.019
18	20	Unbiased	0.4362	0.4299	-0.0063
19	20	Biased	1.7448	1.7509	0.0061
20	50	Unbiased	0.3653	0.4277	0.0624
21	0	Correlation	1.4511	1.4477	-0.0034
22	50	Unbiased	0.0259	0.1044	0.0785
23	0	Correlation	0.7135	0.7184	0.0049
24	20	Biased	1.3225	1.2901	-0.0324
26	50	Biased	2.0024	2.0763	0.0739
27	30	Unbiased	1.5639	1.5924	0.0285
28	30	Biased	0.6502	0.6469	-0.0033
29	30	Unbiased	1.0318	1.0108	-0.021
30	20	Biased	3.0013	2.9732	-0.0281
31	30	Unbiased	2.071	2.089	0.018
33	30	Biased	0.816	0.8304	0.0144
34	50	Unbiased	0.8534	0.9662	0.1128
35	20	Unbiased	-0.0668	-0.0321	0.0347
41	30	Biased	2.0596	1.7314	-0.3282

Test Statistics (mV)

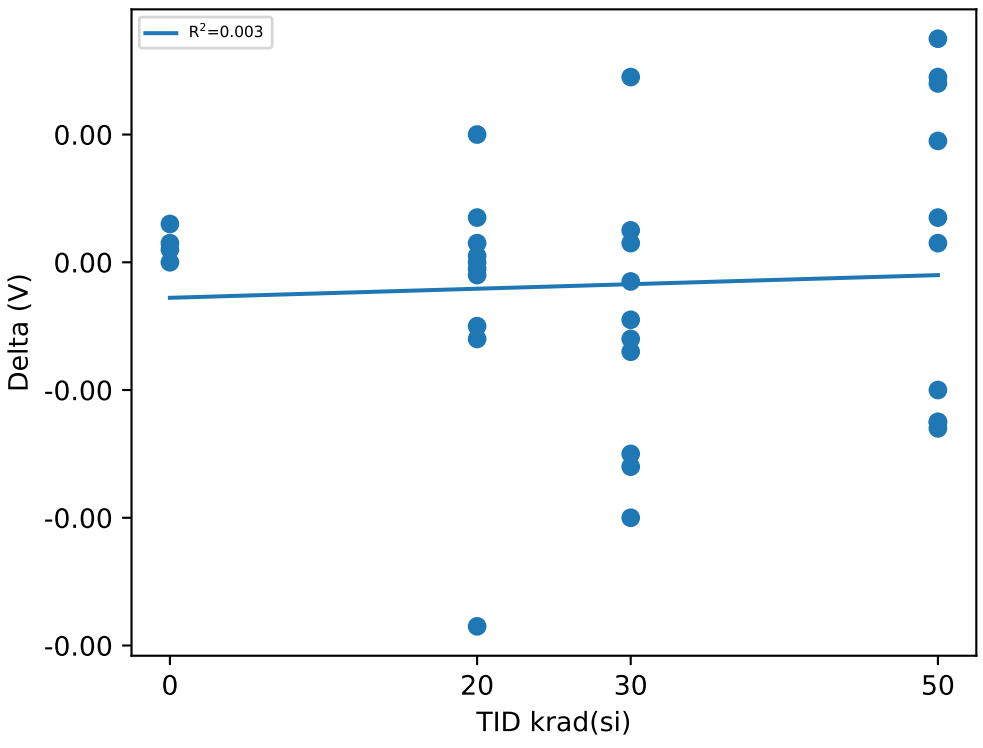
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.142	0.78987	1.4511	0.53751	0.1413	0.78255	1.4477	0.53521	-0.0301	-0.007325	0.0049	0.015572
20	-0.0668	1.315	3.0013	0.96775	-0.0321	1.3114	2.9732	0.96454	-0.0414	-0.00356	0.0446	0.028896
30	0.6502	1.4561	2.071	0.49937	0.6469	1.4263	2.089	0.46959	-0.3282	-0.02986	0.0285	0.10582
50	-0.478	1.1858	2.5498	0.9811	-0.3998	1.2461	2.5723	0.96617	-0.0008	0.06026	0.1128	0.031473

Device Test: 19.58 VOLTAGE|VREF//14/14/0/0/5/1MHz//@VREF_25C

TID vs Result Stats



TID vs Post - Pre Exposure Delta



Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

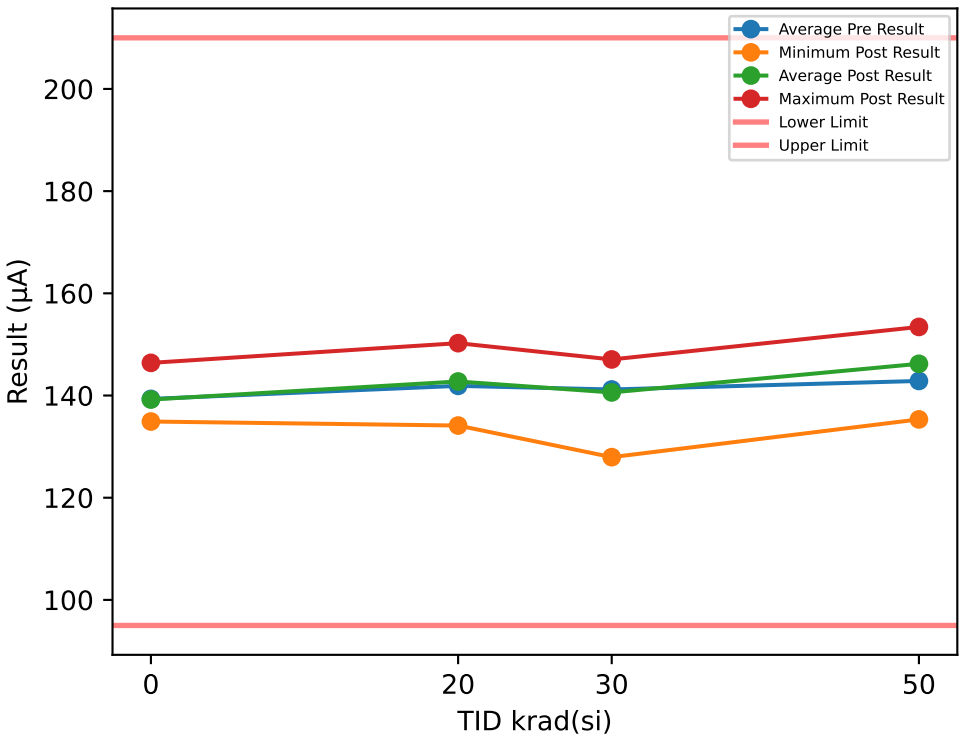
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	0.60011	0.60018	7e-05
2	20	Unbiased	0.60044	0.60043	-1e-05
3	50	Biased	0.59973	0.59947	-0.00026
4	30	Unbiased	0.59995	0.59983	-0.00012
5	50	Unbiased	0.60029	0.60032	3e-05
6	30	Biased	0.59993	0.59961	-0.00032
7	50	Biased	0.59998	0.59973	-0.00025
8	30	Unbiased	0.5999	0.5995	-0.0004
9	20	Unbiased	0.59988	0.60008	0.0002
10	50	Biased	0.59974	0.59949	-0.00025
11	30	Biased	0.6005	0.60036	-0.00014
12	0	Correlation	0.60017	0.60017	0
13	0	Correlation	0.60038	0.60041	3e-05
14	50	Unbiased	0.59999	0.59979	-0.0002
15	20	Biased	0.60006	0.59994	-0.00012
16	20	Unbiased	0.60017	0.60018	1e-05
17	20	Biased	0.60001	0.60008	7e-05
18	20	Unbiased	0.6005	0.59993	-0.00057
19	20	Biased	0.60037	0.60035	-2e-05
20	50	Unbiased	0.60039	0.60058	0.00019
21	0	Correlation	0.60016	0.60022	6e-05
22	50	Unbiased	0.60011	0.60046	0.00035
23	0	Correlation	0.60015	0.60017	2e-05
24	20	Biased	0.60046	0.60049	3e-05
26	50	Biased	0.60017	0.60045	0.00028
27	30	Unbiased	0.60009	0.60014	5e-05
28	30	Biased	0.60045	0.60015	-0.0003
29	30	Unbiased	0.60048	0.60039	-9e-05
30	20	Biased	0.59989	0.59989	0
31	30	Unbiased	0.60043	0.60046	3e-05
33	30	Biased	0.6001	0.60007	-3e-05
34	50	Unbiased	0.60008	0.60037	0.00029
35	20	Unbiased	0.60042	0.60032	-0.0001
41	30	Biased	0.60028	0.60057	0.00029

Test Statistics (V)

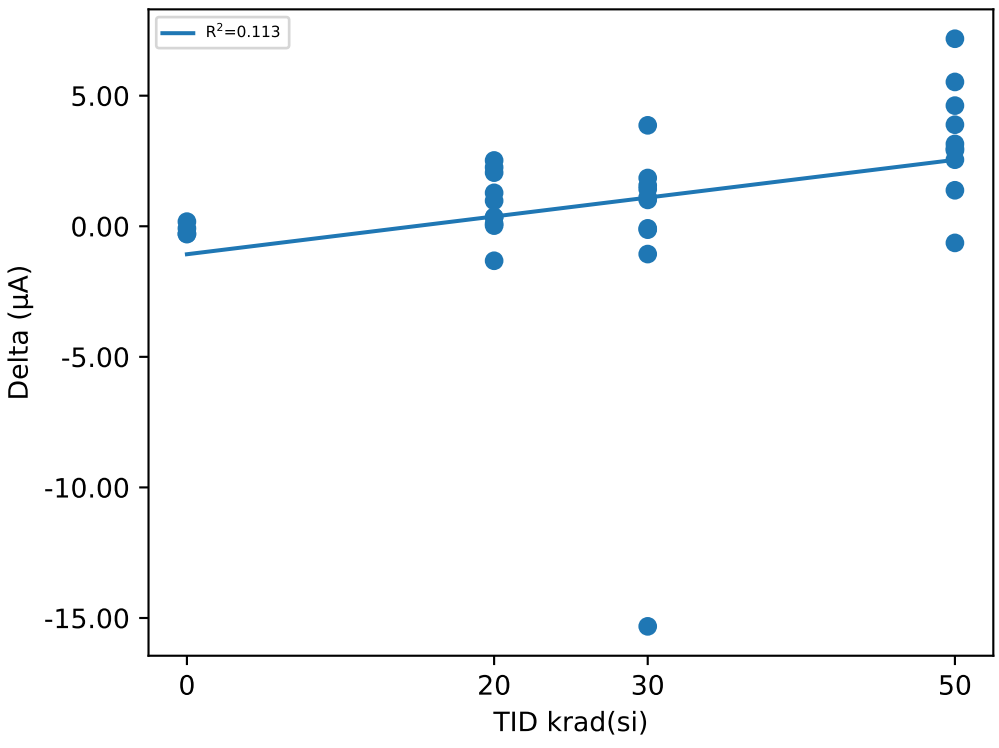
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.60015	0.60021	0.60038	0.0001103	0.60017	0.60024	0.60041	0.00011413	0	2.75e-05	6e-05	2.5e-05
20	0.59988	0.60022	0.6005	0.00024576	0.59989	0.60017	0.60049	0.0002186	-0.00057	-5.1e-05	0.0002	0.00020267
30	0.5999	0.60021	0.6005	0.00024415	0.5995	0.60011	0.60057	0.00036203	-0.0004	-0.000103	0.00029	0.00020462
50	0.59973	0.60006	0.60039	0.00021132	0.59947	0.60008	0.60058	0.00042291	-0.00026	2.5e-05	0.00035	0.00024794

Device Test: 19.6 CURRENT|EA_SOURCE//5/5/0/0/5/500kHz//@EA_I_SOURCE

TID vs Result Stats



TID vs Post - Pre Exposure Delta



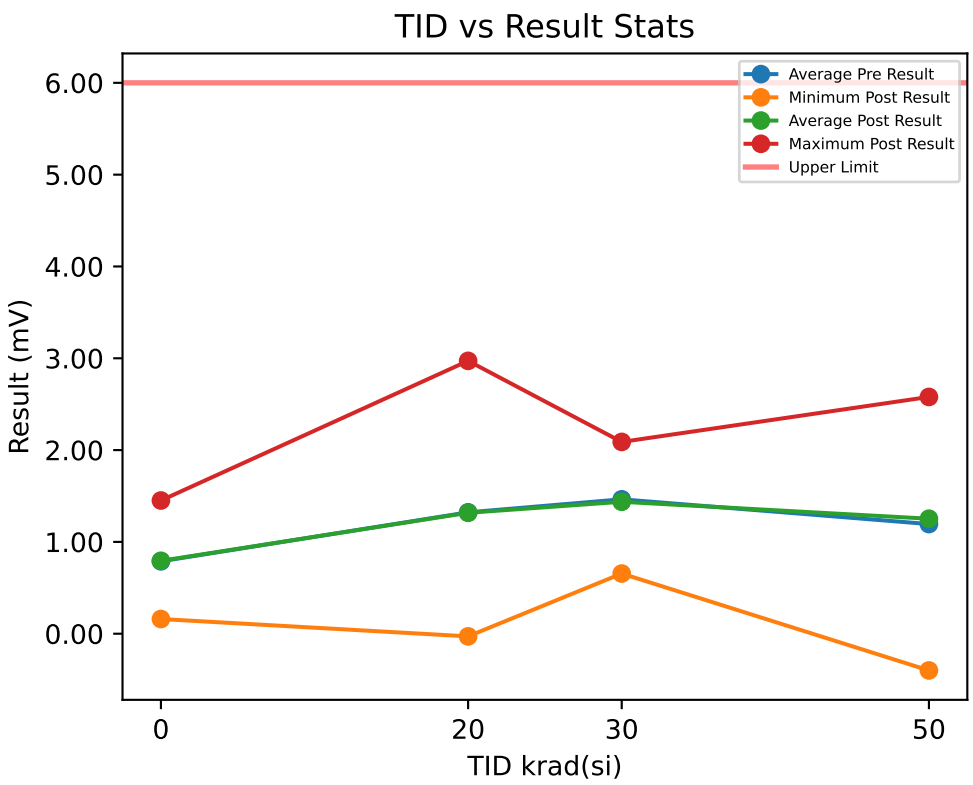
Test Results (Lower Limit = 95.0, Upper Limit = 210.0 (µA))

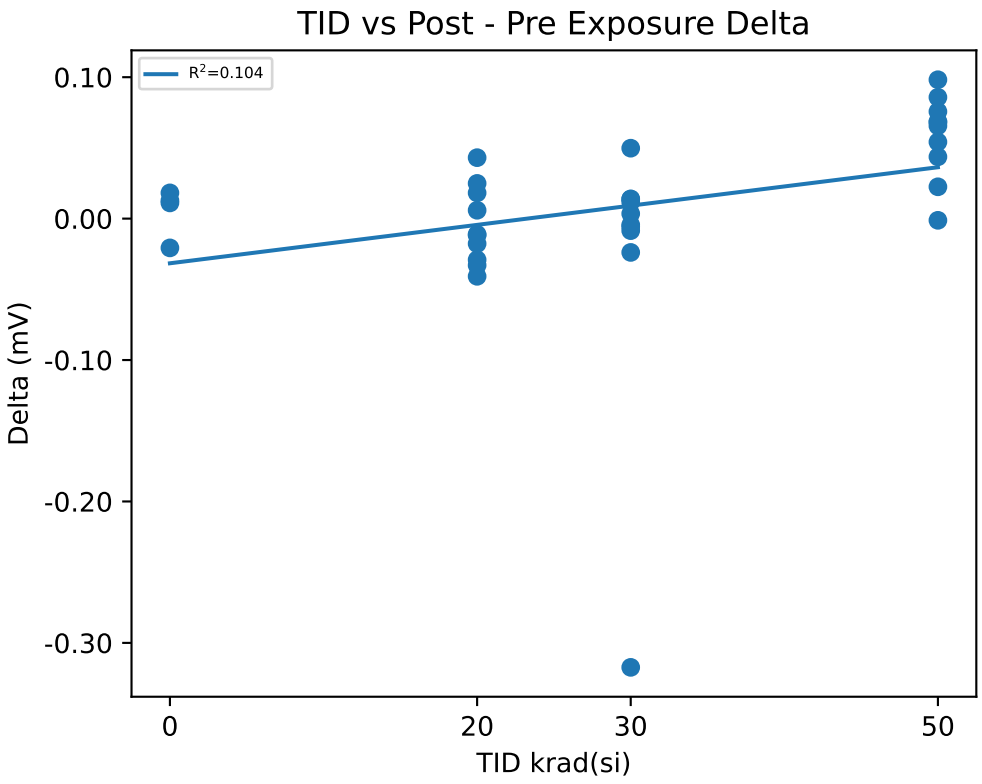
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	140.92	142.3	1.378
2	20	Unbiased	146.41	146.76	0.351
3	50	Biased	135.96	135.33	-0.637
4	30	Unbiased	145.28	146.84	1.5633
5	50	Unbiased	142.09	146.71	4.6198
6	30	Biased	137.62	136.55	-1.0646
7	50	Biased	150.44	153.42	2.9797
8	30	Unbiased	143.42	144.43	1.0095
9	20	Unbiased	135.71	137.76	2.0533
10	50	Biased	145.81	148.97	3.1536
11	30	Biased	139.26	139.13	-0.1308
12	0	Correlation	146.69	146.39	-0.2996
13	0	Correlation	135.55	135.26	-0.288
14	50	Unbiased	146.69	149.6	2.91
15	20	Biased	144.47	143.15	-1.3212
16	20	Unbiased	133.15	134.12	0.9768
17	20	Biased	145.07	146.35	1.28
18	20	Unbiased	149.9	150.25	0.3492
19	20	Biased	145.39	147.64	2.2557
20	50	Unbiased	142.35	146.24	3.8887
21	0	Correlation	140.11	140.28	0.1774
22	50	Unbiased	141.83	149.01	7.1806
23	0	Correlation	134.99	134.91	-0.0802
24	20	Biased	142.26	142.36	0.098
26	50	Biased	139.35	144.87	5.5264
27	30	Unbiased	145.95	147.06	1.1085
28	30	Biased	145.31	146.73	1.4226
29	30	Unbiased	134.92	136.77	1.848
30	20	Biased	140.01	142.53	2.5201
31	30	Unbiased	135.81	135.73	-0.0798
33	30	Biased	140.99	144.85	3.8649
34	50	Unbiased	143.05	145.6	2.5486
35	20	Unbiased	136.53	136.55	0.0244
41	30	Biased	143.26	127.94	-15.32

Test Statistics (µA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	134.99	139.34	146.69	5.4123	134.91	139.21	146.39	5.3781	-0.2996	-0.1226	0.1774	0.22397
20	133.15	141.89	149.9	5.381	134.12	142.75	150.25	5.2407	-1.3212	0.85873	2.5201	1.196
30	134.92	141.18	145.95	4.0871	127.94	140.6	147.06	6.3964	-15.32	-0.57786	3.8649	5.3499
50	135.96	142.85	150.44	4.0349	135.33	146.2	153.42	4.8885	-0.637	3.3548	7.1806	2.163

Device Test: 19.60 VOLTAGE|OFFSET//14/14/0/0/5/1MHz//@EA_OS





Test Results (Upper Limit = 6.0 (mV))

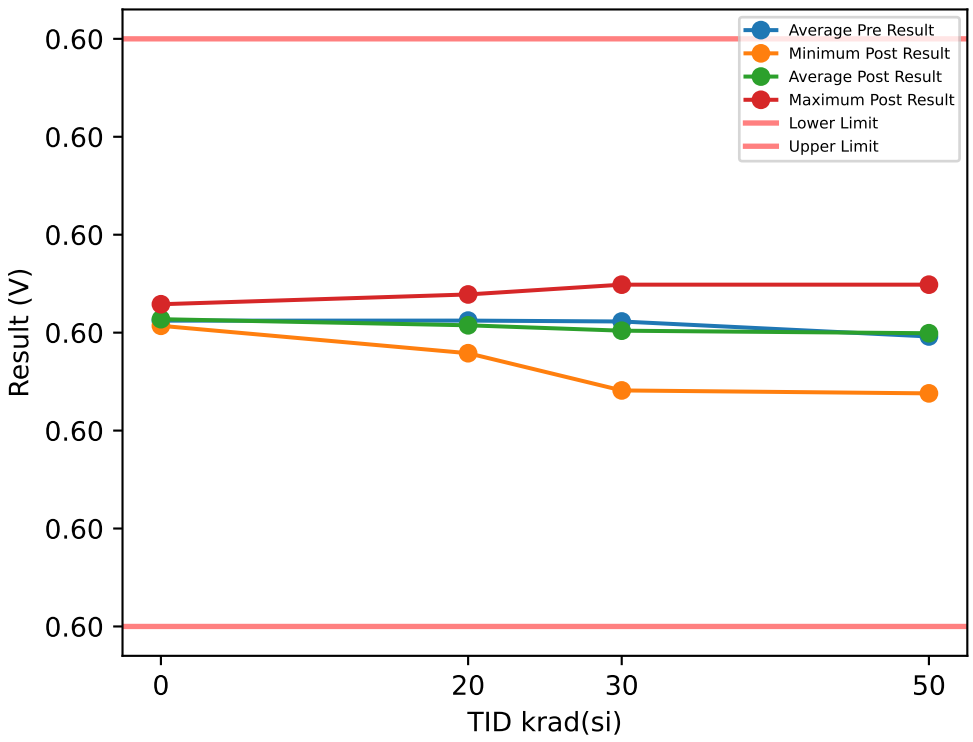
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	1.6645	1.6633	-0.0012
2	20	Unbiased	0.796	0.8142	0.0182
3	50	Biased	-0.4687	-0.4001	0.0686
4	30	Unbiased	1.3579	1.3614	0.0035
5	50	Unbiased	2.5564	2.5789	0.0225
6	30	Biased	1.4305	1.4261	-0.0044
7	50	Biased	1.0984	1.1666	0.0682
8	30	Unbiased	1.8081	1.8024	-0.0057
9	20	Unbiased	2.0615	2.1046	0.0431
10	50	Biased	1.8647	1.9084	0.0437
11	30	Biased	1.8212	1.8329	0.0117
12	0	Correlation	0.8509	0.8302	-0.0207
13	0	Correlation	0.1491	0.1602	0.0111
14	50	Unbiased	1.9442	2.0098	0.0656
15	20	Biased	2.0312	2.0195	-0.0117
16	20	Unbiased	0.2016	0.1608	-0.0408
17	20	Biased	1.6579	1.6468	-0.0111
18	20	Unbiased	0.4519	0.4342	-0.0177
19	20	Biased	1.7459	1.7518	0.0059
20	50	Unbiased	0.375	0.4292	0.0542
21	0	Correlation	1.4381	1.4509	0.0128
22	50	Unbiased	0.0298	0.1055	0.0757
23	0	Correlation	0.7169	0.7351	0.0182
24	20	Biased	1.3298	1.2968	-0.033
26	50	Biased	2.0055	2.0913	0.0858
27	30	Unbiased	1.5639	1.6137	0.0498
28	30	Biased	0.6638	0.6553	-0.0085
29	30	Unbiased	1.0373	1.0134	-0.0239
30	20	Biased	3.001	2.9719	-0.0291
31	30	Unbiased	2.0752	2.089	0.0138
33	30	Biased	0.8215	0.8354	0.0139
34	50	Unbiased	0.8745	0.9727	0.0982
35	20	Unbiased	-0.0537	-0.0288	0.0249
41	30	Biased	2.0583	1.741	-0.3173

Test Statistics (mV)

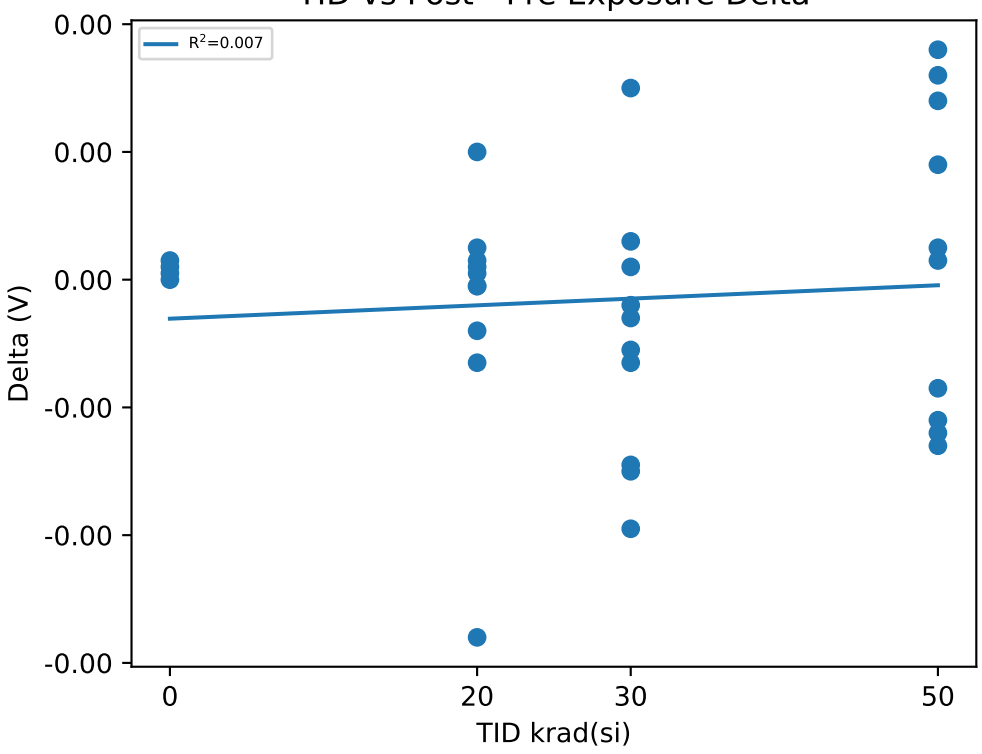
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.1491	0.78875	1.4381	0.5291	0.1602	0.7941	1.4509	0.52852	-0.0207	0.00535	0.0182	0.017628
20	-0.0537	1.3223	3.001	0.96281	-0.0288	1.3172	2.9719	0.96211	-0.0408	-0.00513	0.0431	0.027395
30	0.6638	1.4638	2.0752	0.49781	0.6553	1.4371	2.089	0.47108	-0.3173	-0.02671	0.0498	0.10395
50	-0.4687	1.1944	2.5564	0.9804	-0.4001	1.2526	2.5789	0.96871	-0.0012	0.05813	0.0982	0.02974

Device Test: 19.61 VOLTAGE|VREF//4.5/4.5/0/1000/4.5/100kHz//@VREF_25C

TID vs Result Stats



TID vs Post - Pre Exposure Delta



Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

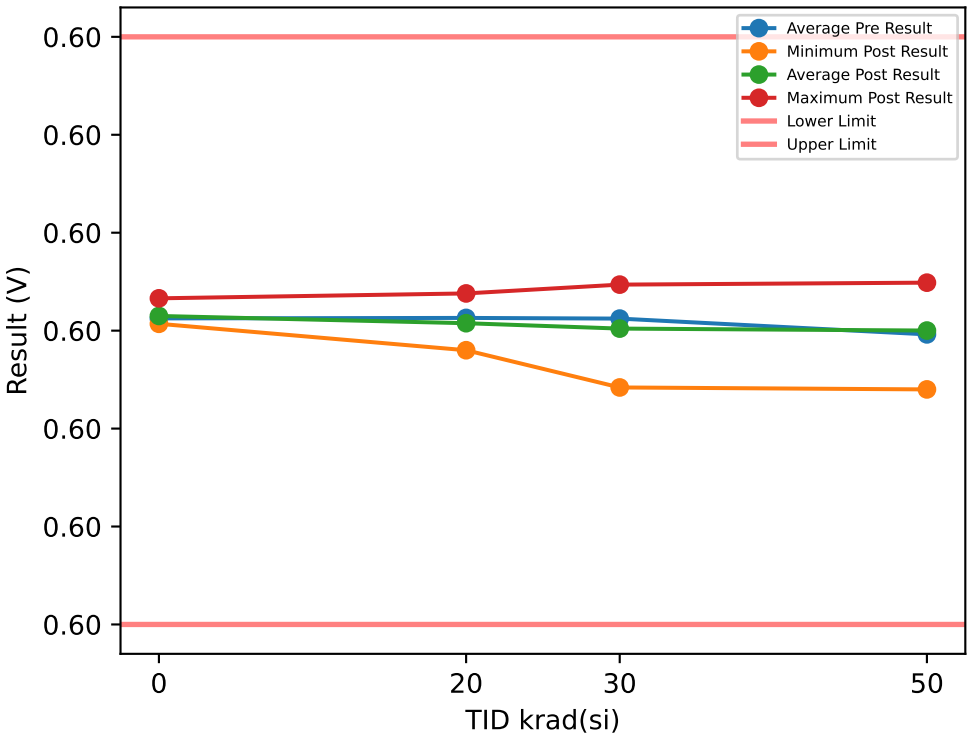
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	0.60004	0.60009	5e-05
2	20	Unbiased	0.60033	0.60035	2e-05
3	50	Biased	0.59964	0.59938	-0.00026
4	30	Unbiased	0.59985	0.59974	-0.00011
5	50	Unbiased	0.60021	0.60024	3e-05
6	30	Biased	0.59983	0.59953	-0.0003
7	50	Biased	0.59988	0.59964	-0.00024
8	30	Unbiased	0.5998	0.59941	-0.00039
9	20	Unbiased	0.59979	0.59999	0.0002
10	50	Biased	0.59963	0.59941	-0.00022
11	30	Biased	0.6004	0.60027	-0.00013
12	0	Correlation	0.60008	0.60008	0
13	0	Correlation	0.60027	0.60029	2e-05
14	50	Unbiased	0.59988	0.59971	-0.00017
15	20	Biased	0.59999	0.59986	-0.00013
16	20	Unbiased	0.60007	0.60006	-1e-05
17	20	Biased	0.59993	0.59998	5e-05
18	20	Unbiased	0.60038	0.59982	-0.00056
19	20	Biased	0.60029	0.60028	-1e-05
20	50	Unbiased	0.60031	0.60049	0.00018
21	0	Correlation	0.60008	0.60011	3e-05
22	50	Unbiased	0.60001	0.60037	0.00036
23	0	Correlation	0.60006	0.60007	1e-05
24	20	Biased	0.60036	0.60039	3e-05
26	50	Biased	0.60006	0.60034	0.00028
27	30	Unbiased	0.59999	0.60005	6e-05
28	30	Biased	0.60033	0.60004	-0.00029
29	30	Unbiased	0.60038	0.60032	-6e-05
30	20	Biased	0.59978	0.59979	1e-05
31	30	Unbiased	0.60035	0.60037	2e-05
33	30	Biased	0.60002	0.59998	-4e-05
34	50	Unbiased	0.59995	0.60027	0.00032
35	20	Unbiased	0.60031	0.60023	-8e-05
41	30	Biased	0.60019	0.60049	0.0003

Test Statistics (V)

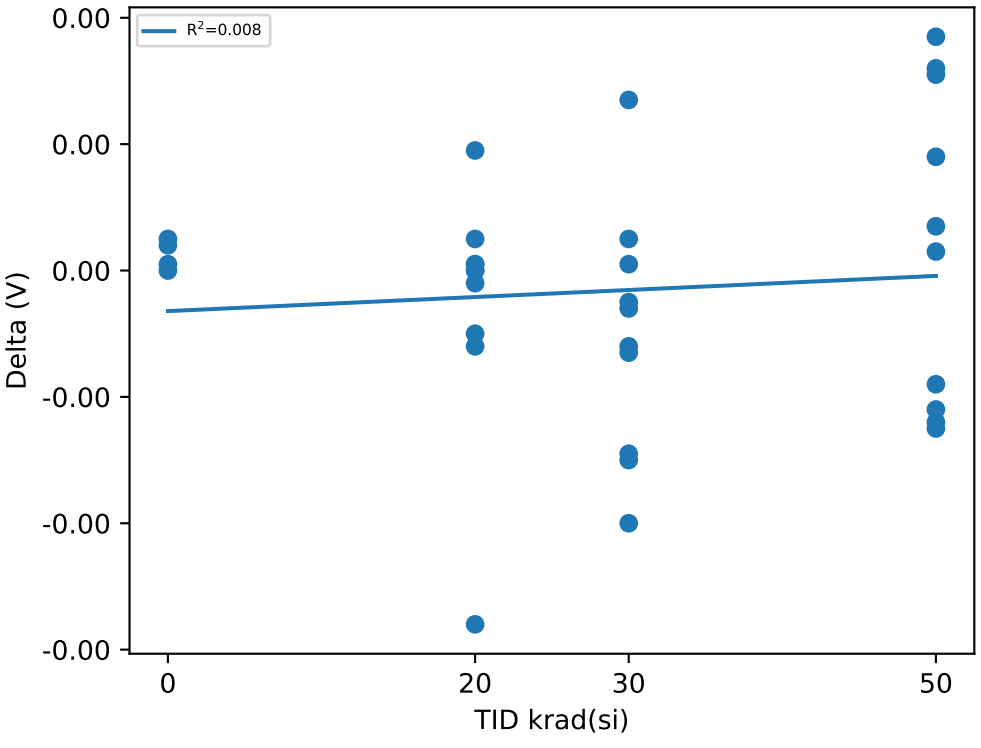
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.60006	0.60012	0.60027	9.8784e-05	0.60007	0.60014	0.60029	0.00010308	0	1.5e-05	3e-05	1.291e-05
20	0.59978	0.60012	0.60038	0.00023903	0.59979	0.60008	0.60039	0.00022357	-0.00056	-4.8e-05	0.0002	0.00019943
30	0.5998	0.60011	0.6004	0.00024355	0.59941	0.60002	0.60049	0.00036353	-0.00039	-9.4e-05	0.0003	0.00020167
50	0.59963	0.59996	0.60031	0.0002181	0.59938	0.59999	0.60049	0.0004186	-0.00026	3.3e-05	0.00036	0.00024445

Device Test: 19.63 VOLTAGE|VREF//5/5/0/1000/5/100kHz//@VREF_25C

TID vs Result Stats



TID vs Post - Pre Exposure Delta



Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

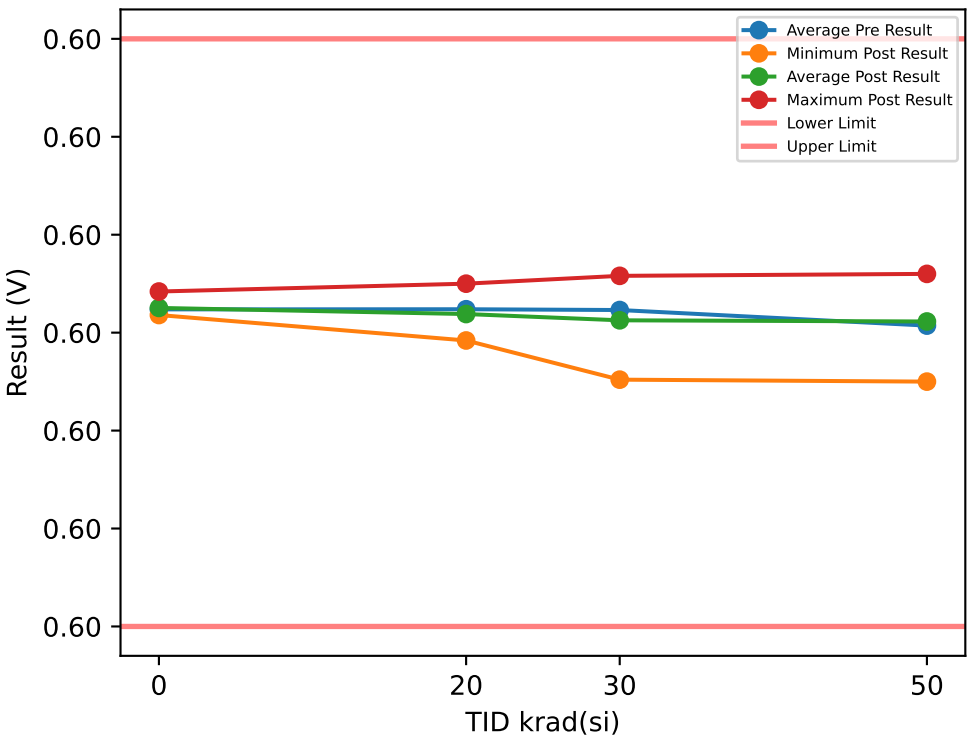
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	0.60003	0.6001	7e-05
2	20	Unbiased	0.60033	0.60034	1e-05
3	50	Biased	0.59964	0.5994	-0.00024
4	30	Unbiased	0.59985	0.59973	-0.00012
5	50	Unbiased	0.60021	0.60024	3e-05
6	30	Biased	0.59982	0.59953	-0.00029
7	50	Biased	0.5999	0.59965	-0.00025
8	30	Unbiased	0.59982	0.59942	-0.0004
9	20	Unbiased	0.5998	0.59999	0.00019
10	50	Biased	0.59963	0.59941	-0.00022
11	30	Biased	0.60041	0.60028	-0.00013
12	0	Correlation	0.60008	0.60008	0
13	0	Correlation	0.60028	0.60033	5e-05
14	50	Unbiased	0.59988	0.5997	-0.00018
15	20	Biased	0.59998	0.59986	-0.00012
16	20	Unbiased	0.60008	0.60006	-2e-05
17	20	Biased	0.59993	0.59998	5e-05
18	20	Unbiased	0.60039	0.59983	-0.00056
19	20	Biased	0.60029	0.60029	0
20	50	Unbiased	0.60031	0.60049	0.00018
21	0	Correlation	0.60008	0.60012	4e-05
22	50	Unbiased	0.6	0.60037	0.00037
23	0	Correlation	0.60006	0.60007	1e-05
24	20	Biased	0.60037	0.60038	1e-05
26	50	Biased	0.60006	0.60037	0.00031
27	30	Unbiased	0.6	0.60005	5e-05
28	30	Biased	0.60035	0.60005	-0.0003
29	30	Unbiased	0.60039	0.60033	-6e-05
30	20	Biased	0.5998	0.5998	0
31	30	Unbiased	0.60036	0.60037	1e-05
33	30	Biased	0.60003	0.59998	-5e-05
34	50	Unbiased	0.59996	0.60028	0.00032
35	20	Unbiased	0.60033	0.60023	-0.0001
41	30	Biased	0.6002	0.60047	0.00027

Test Statistics (V)

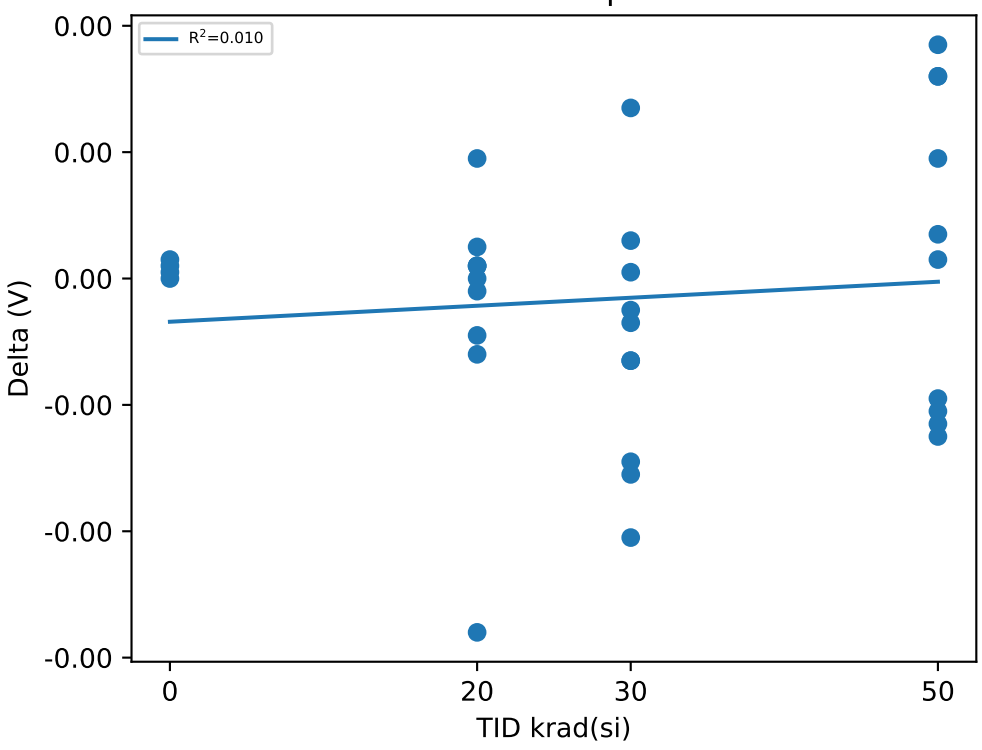
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.60006	0.60013	0.60028	0.00010376	0.60007	0.60015	0.60033	0.00012193	0	2.5e-05	5e-05	2.3805e-05
20	0.5998	0.60013	0.60039	0.00023889	0.5998	0.60008	0.60038	0.00021905	-0.00056	-5.4e-05	0.00019	0.00019665
30	0.59982	0.60012	0.60041	0.00024703	0.59942	0.60002	0.60047	0.00036152	-0.0004	-0.000102	0.00027	0.00019521
50	0.59963	0.59996	0.60031	0.00021673	0.5994	0.6	0.60049	0.00041906	-0.00025	3.9e-05	0.00037	0.00024929

Device Test: 19.65 VOLTAGE|VREF//12/12/0/1000/5/100kHz//@VREF_25C

TID vs Result Stats



TID vs Post - Pre Exposure Delta



Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

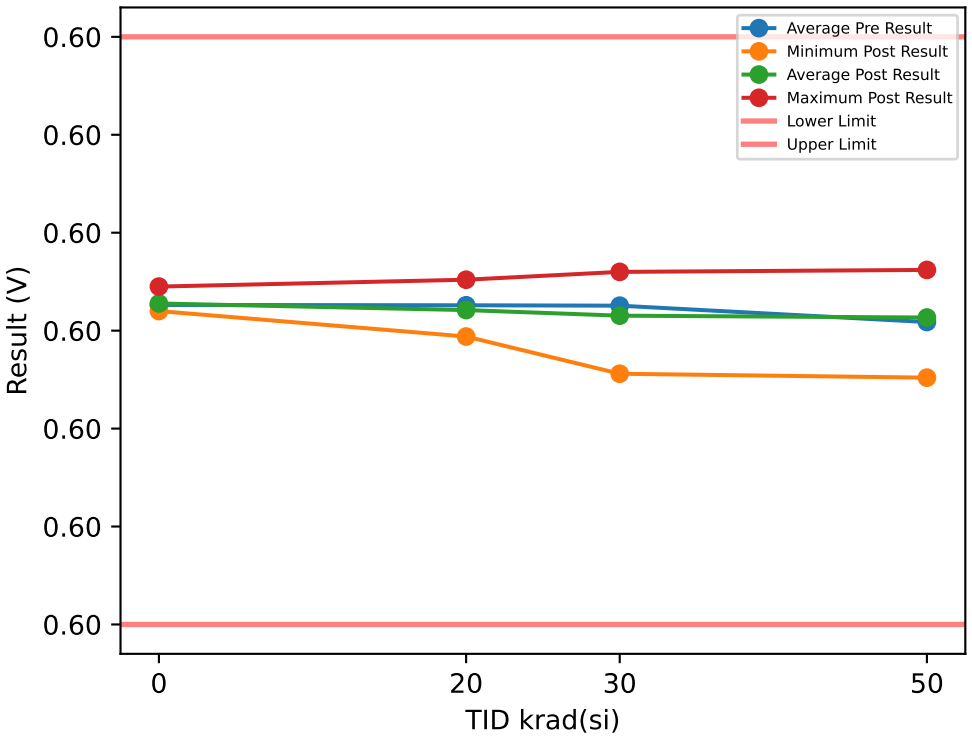
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	0.60015	0.60022	7e-05
2	20	Unbiased	0.60044	0.60046	2e-05
3	50	Biased	0.59975	0.5995	-0.00025
4	30	Unbiased	0.59997	0.59984	-0.00013
5	50	Unbiased	0.60032	0.60035	3e-05
6	30	Biased	0.59992	0.59963	-0.00029
7	50	Biased	0.6	0.59977	-0.00023
8	30	Unbiased	0.59993	0.59952	-0.00041
9	20	Unbiased	0.59991	0.6001	0.00019
10	50	Biased	0.59974	0.59953	-0.00021
11	30	Biased	0.60052	0.60039	-0.00013
12	0	Correlation	0.60018	0.60018	0
13	0	Correlation	0.6004	0.60042	2e-05
14	50	Unbiased	0.6	0.59981	-0.00019
15	20	Biased	0.60008	0.59996	-0.00012
16	20	Unbiased	0.6002	0.60018	-2e-05
17	20	Biased	0.60004	0.60009	5e-05
18	20	Unbiased	0.6005	0.59994	-0.00056
19	20	Biased	0.6004	0.6004	0
20	50	Unbiased	0.60041	0.6006	0.00019
21	0	Correlation	0.6002	0.60023	3e-05
22	50	Unbiased	0.60011	0.60048	0.00037
23	0	Correlation	0.60017	0.60018	1e-05
24	20	Biased	0.60048	0.6005	2e-05
26	50	Biased	0.60016	0.60048	0.00032
27	30	Unbiased	0.6001	0.60016	6e-05
28	30	Biased	0.60046	0.60015	-0.00031
29	30	Unbiased	0.6005	0.60043	-7e-05
30	20	Biased	0.5999	0.59992	2e-05
31	30	Unbiased	0.60046	0.60047	1e-05
33	30	Biased	0.60014	0.60009	-5e-05
34	50	Unbiased	0.60008	0.6004	0.00032
35	20	Unbiased	0.60044	0.60035	-9e-05
41	30	Biased	0.60031	0.60058	0.00027

Test Statistics (V)

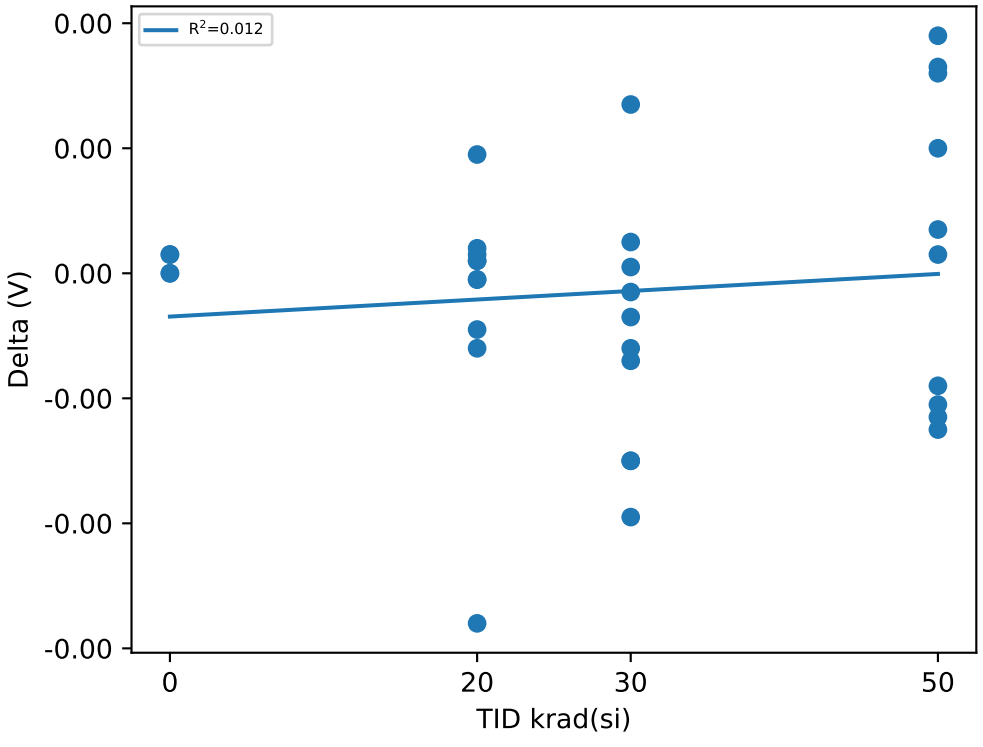
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.60017	0.60024	0.6004	0.00010905	0.60018	0.60025	0.60042	0.00011413	0	1.5e-05	3e-05	1.291e-05
20	0.5999	0.60024	0.6005	0.00024094	0.59992	0.60019	0.6005	0.00022241	-0.00056	-4.9e-05	0.00019	0.00019785
30	0.59992	0.60023	0.60052	0.00024673	0.59952	0.60013	0.60058	0.0003628	-0.00041	-0.000105	0.00027	0.00019884
50	0.59974	0.60007	0.60041	0.00021483	0.5995	0.60011	0.6006	0.00041921	-0.00025	4.2e-05	0.00037	0.00024979

Device Test: 19.67 VOLTAGE|VREF//14/14/0/1000/5/100kHz//@VREF_25C

TID vs Result Stats



TID vs Post - Pre Exposure Delta



Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

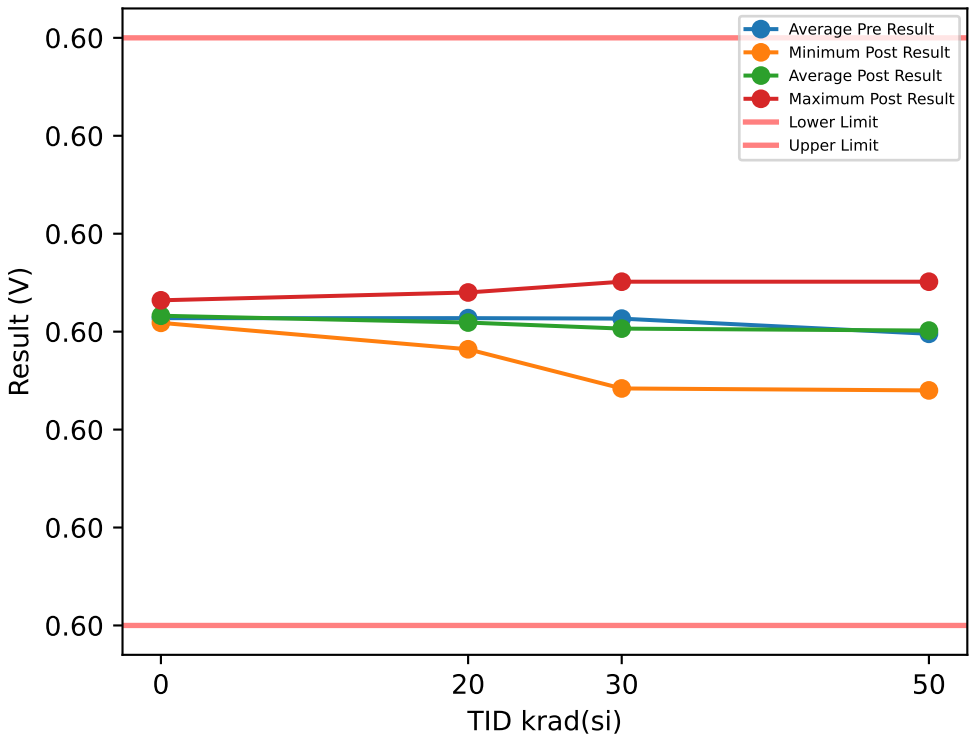
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	0.60017	0.60024	7e-05
2	20	Unbiased	0.60047	0.60049	2e-05
3	50	Biased	0.59977	0.59952	-0.00025
4	30	Unbiased	0.59999	0.59987	-0.00012
5	50	Unbiased	0.60034	0.60037	3e-05
6	30	Biased	0.59996	0.59966	-0.0003
7	50	Biased	0.60001	0.59978	-0.00023
8	30	Unbiased	0.59995	0.59956	-0.00039
9	20	Unbiased	0.59993	0.60012	0.00019
10	50	Biased	0.59976	0.59955	-0.00021
11	30	Biased	0.60055	0.60041	-0.00014
12	0	Correlation	0.60021	0.60021	0
13	0	Correlation	0.60042	0.60045	3e-05
14	50	Unbiased	0.60001	0.59983	-0.00018
15	20	Biased	0.6001	0.59998	-0.00012
16	20	Unbiased	0.60021	0.6002	-1e-05
17	20	Biased	0.60007	0.60011	4e-05
18	20	Unbiased	0.60052	0.59996	-0.00056
19	20	Biased	0.60042	0.60041	-1e-05
20	50	Unbiased	0.60042	0.60062	0.0002
21	0	Correlation	0.60022	0.60025	3e-05
22	50	Unbiased	0.60013	0.60051	0.00038
23	0	Correlation	0.6002	0.6002	0
24	20	Biased	0.6005	0.60052	2e-05
26	50	Biased	0.60017	0.6005	0.00033
27	30	Unbiased	0.60013	0.60018	5e-05
28	30	Biased	0.60048	0.60018	-0.0003
29	30	Unbiased	0.60052	0.60045	-7e-05
30	20	Biased	0.59991	0.59994	3e-05
31	30	Unbiased	0.60049	0.6005	1e-05
33	30	Biased	0.60015	0.60012	-3e-05
34	50	Unbiased	0.6001	0.60042	0.00032
35	20	Unbiased	0.60046	0.60037	-9e-05
41	30	Biased	0.60033	0.6006	0.00027

Test Statistics (V)

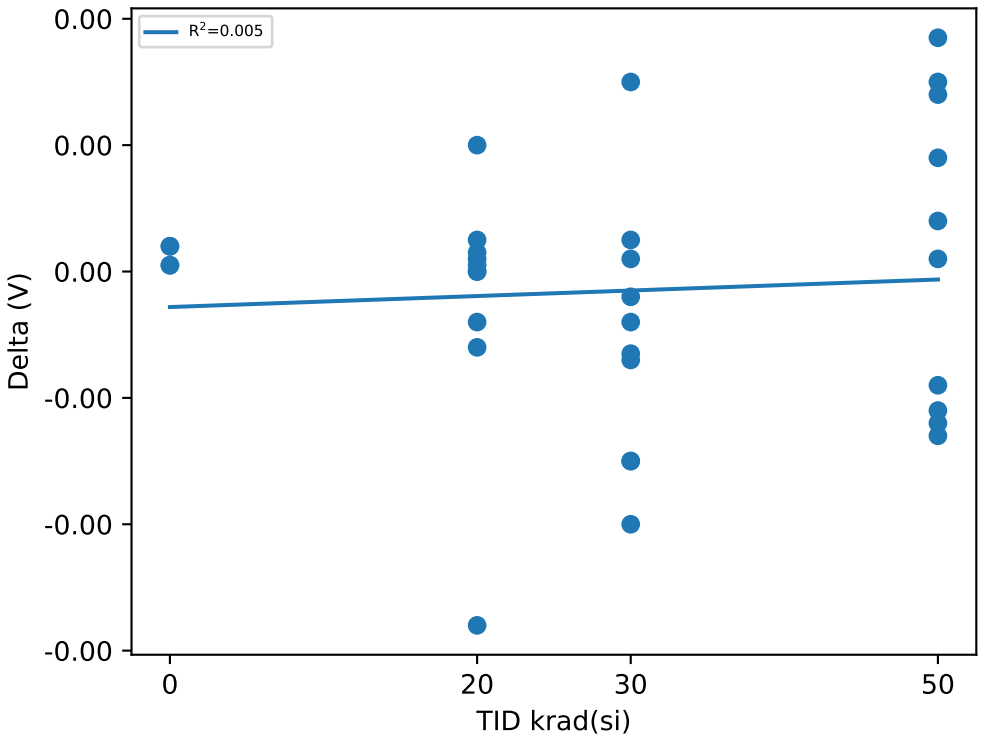
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.6002	0.60026	0.60042	0.00010532	0.6002	0.60028	0.60045	0.00011701	0	1.5e-05	3e-05	1.7321e-05
20	0.59991	0.60026	0.60052	0.00024278	0.59994	0.60021	0.60052	0.00022276	-0.00056	-4.9e-05	0.00019	0.00019768
30	0.59995	0.60025	0.60055	0.00024623	0.59956	0.60015	0.6006	0.00035774	-0.00039	-0.000102	0.00027	0.00019532
50	0.59976	0.60009	0.60042	0.00021343	0.59952	0.60013	0.60062	0.00042111	-0.00025	4.6e-05	0.00038	0.00025216

Device Test: 19.69 VOLTAGE|VREF//4.5/4.5/0/1000/4.5/500kHz//@VREF_25C

TID vs Result Stats



TID vs Post - Pre Exposure Delta



Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

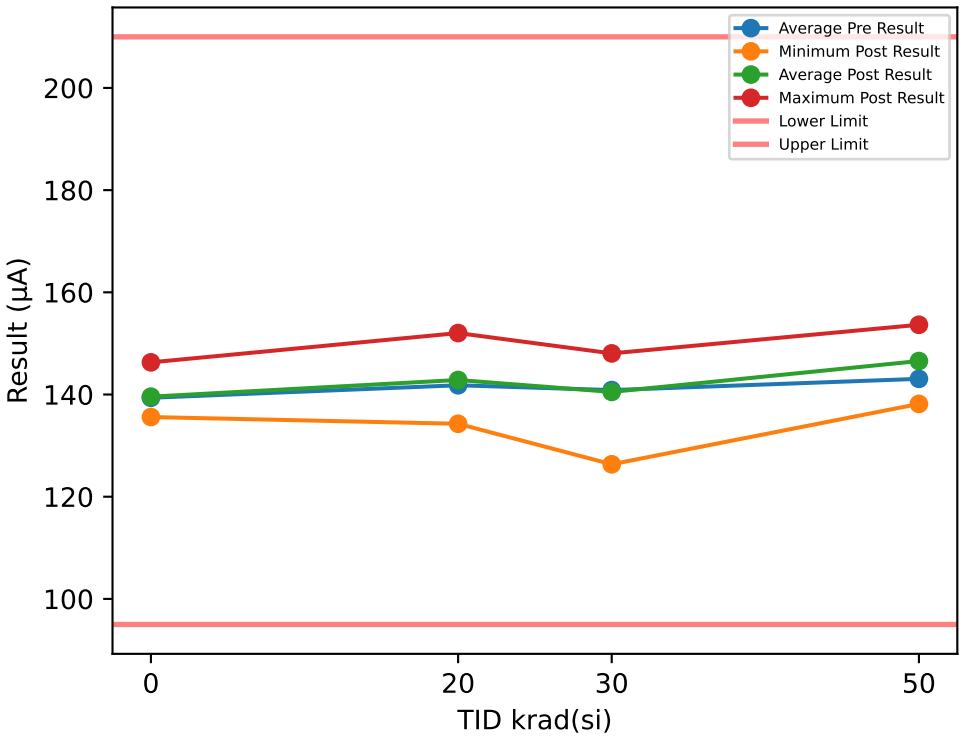
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	0.60004	0.60012	8e-05
2	20	Unbiased	0.60036	0.60037	1e-05
3	50	Biased	0.59966	0.5994	-0.00026
4	30	Unbiased	0.59987	0.59974	-0.00013
5	50	Unbiased	0.60023	0.60025	2e-05
6	30	Biased	0.59984	0.59954	-0.0003
7	50	Biased	0.59989	0.59965	-0.00024
8	30	Unbiased	0.59982	0.59942	-0.0004
9	20	Unbiased	0.5998	0.6	0.0002
10	50	Biased	0.59965	0.59943	-0.00022
11	30	Biased	0.60042	0.60028	-0.00014
12	0	Correlation	0.60009	0.6001	1e-05
13	0	Correlation	0.60028	0.60032	4e-05
14	50	Unbiased	0.59991	0.59973	-0.00018
15	20	Biased	0.6	0.59988	-0.00012
16	20	Unbiased	0.60008	0.60008	0
17	20	Biased	0.59995	0.6	5e-05
18	20	Unbiased	0.6004	0.59984	-0.00056
19	20	Biased	0.6003	0.6003	0
20	50	Unbiased	0.60033	0.60051	0.00018
21	0	Correlation	0.6001	0.60014	4e-05
22	50	Unbiased	0.60001	0.60038	0.00037
23	0	Correlation	0.60008	0.60009	1e-05
24	20	Biased	0.60038	0.6004	2e-05
26	50	Biased	0.60009	0.60037	0.00028
27	30	Unbiased	0.60001	0.60006	5e-05
28	30	Biased	0.60035	0.60005	-0.0003
29	30	Unbiased	0.6004	0.60032	-8e-05
30	20	Biased	0.59979	0.59982	3e-05
31	30	Unbiased	0.60037	0.60039	2e-05
33	30	Biased	0.60004	0.6	-4e-05
34	50	Unbiased	0.59997	0.60027	0.0003
35	20	Unbiased	0.60032	0.60024	-8e-05
41	30	Biased	0.60021	0.60051	0.0003

Test Statistics (V)

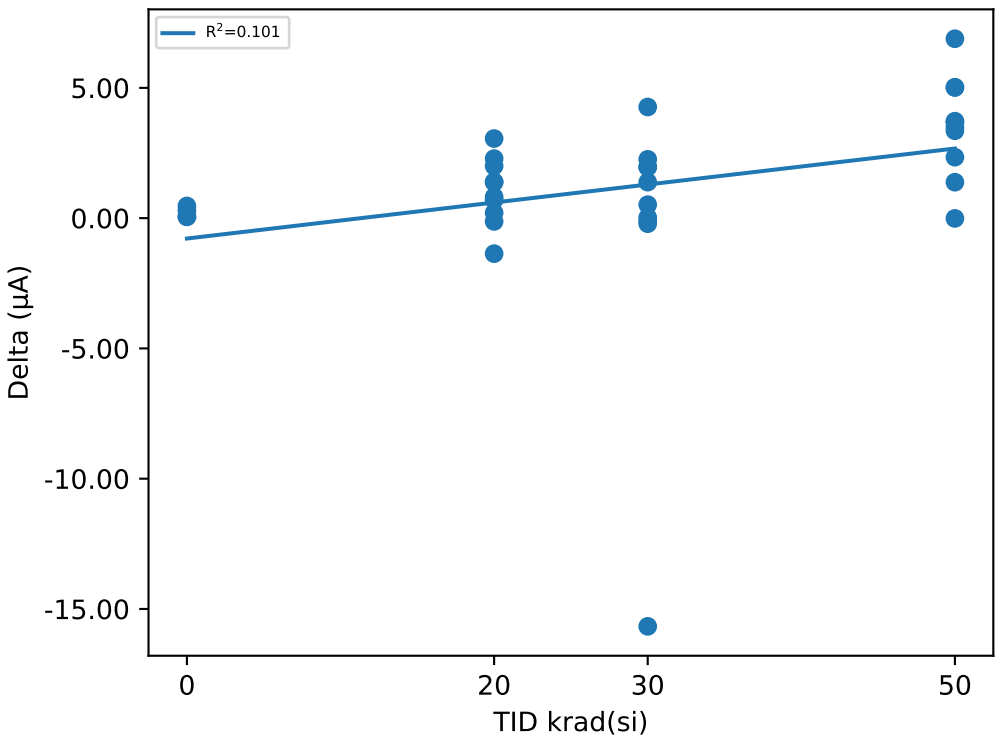
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.60008	0.60014	0.60028	9.535e-05	0.60009	0.60016	0.60032	0.0001072	1e-05	2.5e-05	4e-05	1.7321e-05
20	0.59979	0.60014	0.6004	0.00024243	0.59982	0.60009	0.6004	0.00022031	-0.00056	-4.5e-05	0.0002	0.00019946
30	0.59982	0.60013	0.60042	0.00024486	0.59942	0.60003	0.60051	0.00036592	-0.0004	-0.000102	0.0003	0.00020368
50	0.59965	0.59998	0.60033	0.00021755	0.5994	0.60001	0.60051	0.0004177	-0.00026	3.3e-05	0.00037	0.00024486

Device Test: 19.7 CURRENT|EA_SINK//5/5/0/0/5/500kHz//@EA_I_SINK

TID vs Result Stats



TID vs Post - Pre Exposure Delta



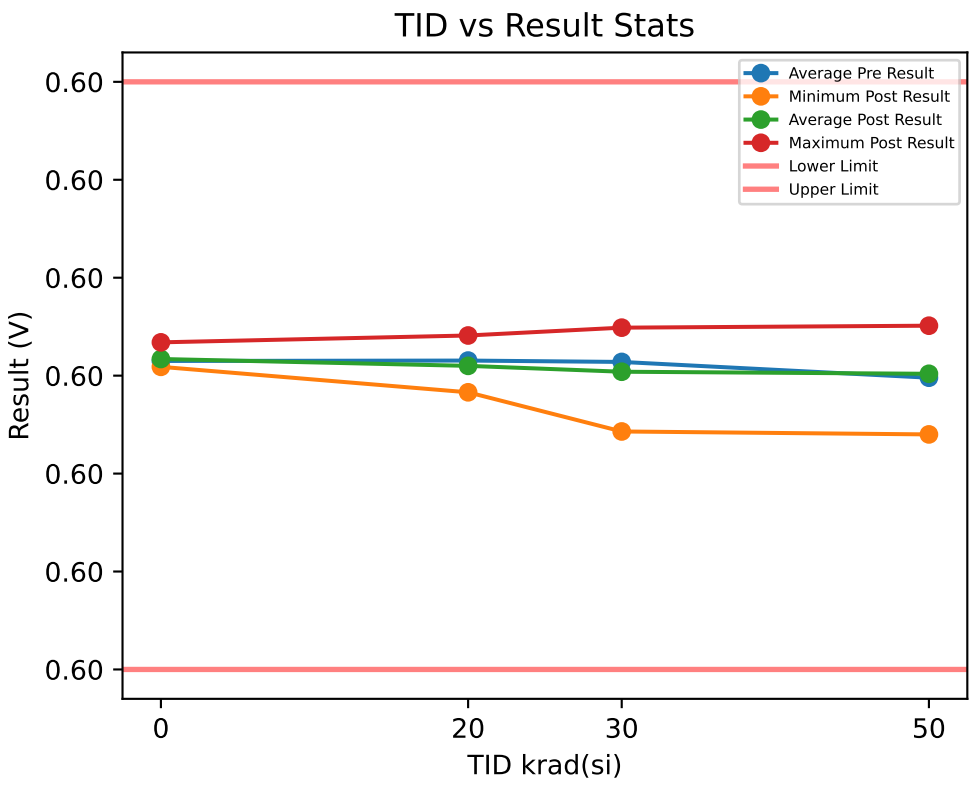
Test Results (Lower Limit = 95.0, Upper Limit = 210.0 (µA))

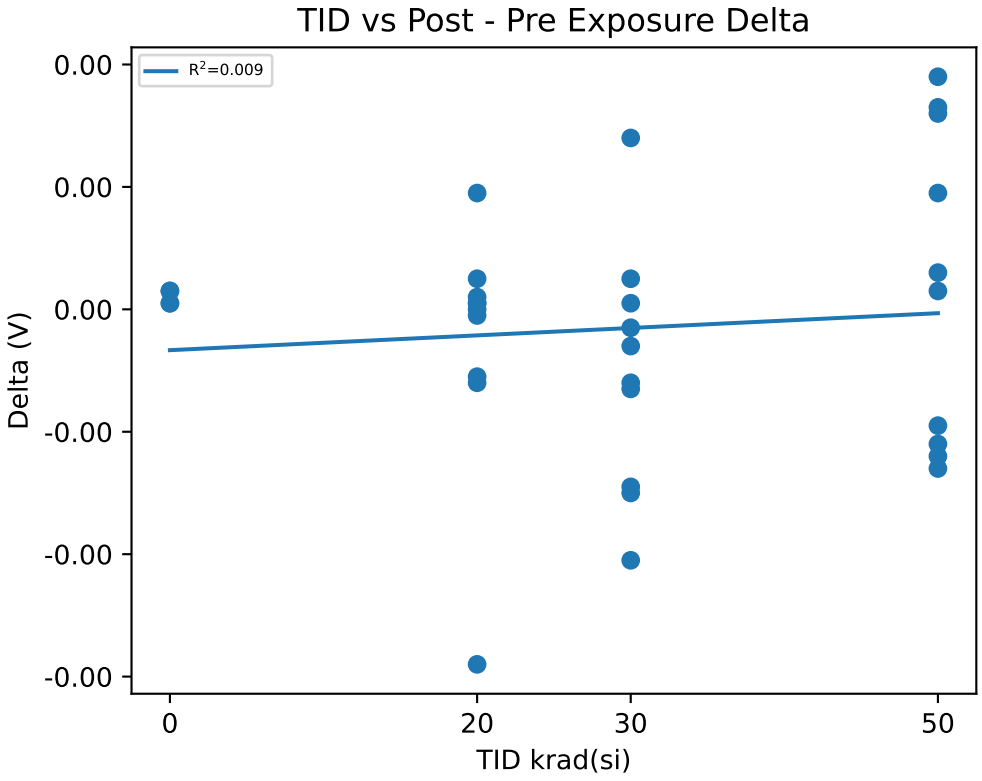
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	140.96	142.34	1.3795
2	20	Unbiased	146.47	147.18	0.7069
3	50	Biased	138.17	138.16	-0.0103
4	30	Unbiased	146.09	148.05	1.9601
5	50	Unbiased	141.09	146.11	5.0207
6	30	Biased	139.06	138.85	-0.2131
7	50	Biased	150.29	153.65	3.3543
8	30	Unbiased	142.85	144.23	1.3821
9	20	Unbiased	135.31	137.31	2.0004
10	50	Biased	145.72	149.44	3.7209
11	30	Biased	137.7	137.59	-0.1112
12	0	Correlation	146.25	146.3	0.0494
13	0	Correlation	135.94	135.99	0.0591
14	50	Unbiased	146.97	150.47	3.4941
15	20	Biased	145.18	143.81	-1.3631
16	20	Unbiased	133.46	134.27	0.8153
17	20	Biased	144.45	145.84	1.3904
18	20	Unbiased	150.65	152.03	1.3806
19	20	Biased	145.05	147.33	2.2847
20	50	Unbiased	142.54	146.23	3.6891
21	0	Correlation	140.14	140.43	0.2883
22	50	Unbiased	143.24	150.12	6.8854
23	0	Correlation	135.13	135.59	0.4669
24	20	Biased	142.04	141.91	-0.1264
26	50	Biased	138.84	143.86	5.0171
27	30	Unbiased	146.71	147.23	0.5179
28	30	Biased	145.74	147.71	1.9686
29	30	Unbiased	134.4	136.65	2.2578
30	20	Biased	138.84	141.9	3.0552
31	30	Unbiased	134.22	134.24	0.0263
33	30	Biased	139.89	144.16	4.2657
34	50	Unbiased	142.83	145.17	2.3389
35	20	Unbiased	136.66	136.87	0.2022
41	30	Biased	142.01	126.35	-15.667

Test Statistics (µA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	135.13	139.36	146.25	5.0888	135.59	139.58	146.3	4.9858	0.0494	0.21592	0.4669	0.20046
20	133.46	141.81	150.65	5.5376	134.27	142.84	152.03	5.5257	-1.3631	1.0346	3.0552	1.2811
30	134.22	140.87	146.71	4.6049	126.35	140.51	148.05	7.0488	-15.667	-0.36132	4.2657	5.5519
50	138.17	143.06	150.29	3.7278	138.16	146.55	153.65	4.5263	-0.0103	3.489	6.8854	1.9535

Device Test: 19.71 VOLTAGE|VREF//5/5/0/1000/5/500kHz//@VREF_25C





Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

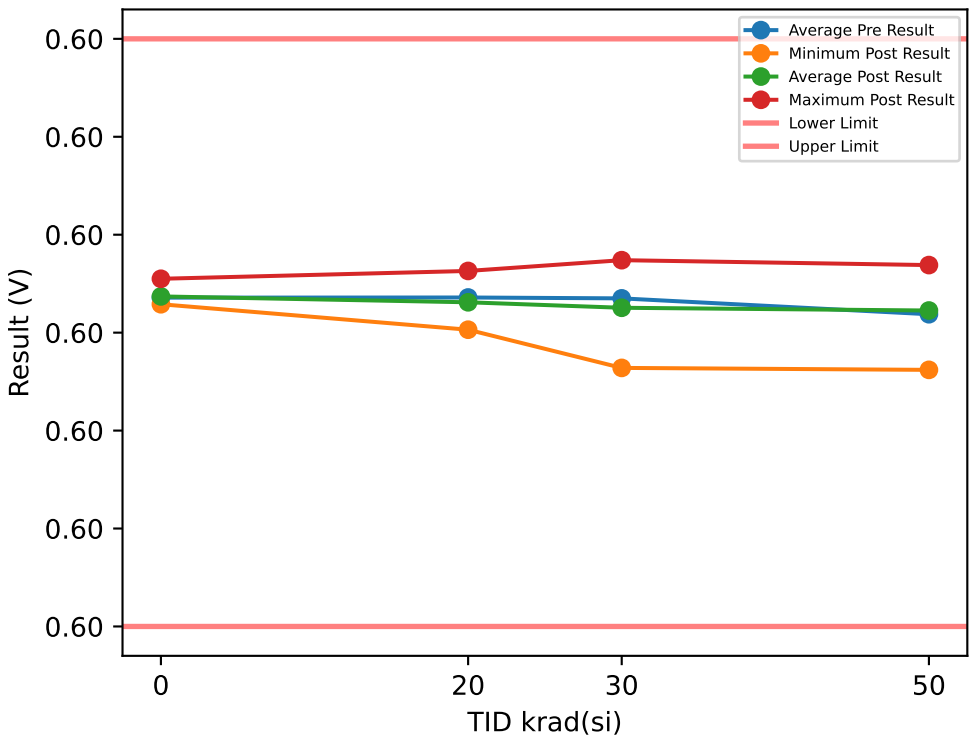
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	0.60006	0.60012	6e-05
2	20	Unbiased	0.60037	0.60037	0
3	50	Biased	0.59966	0.5994	-0.00026
4	30	Unbiased	0.59986	0.59974	-0.00012
5	50	Unbiased	0.60022	0.60025	3e-05
6	30	Biased	0.59984	0.59955	-0.00029
7	50	Biased	0.59991	0.59967	-0.00024
8	30	Unbiased	0.59984	0.59943	-0.00041
9	20	Unbiased	0.59982	0.60001	0.00019
10	50	Biased	0.59966	0.59944	-0.00022
11	30	Biased	0.60043	0.6003	-0.00013
12	0	Correlation	0.6001	0.60011	1e-05
13	0	Correlation	0.60031	0.60034	3e-05
14	50	Unbiased	0.5999	0.59971	-0.00019
15	20	Biased	0.6	0.59988	-0.00012
16	20	Unbiased	0.60009	0.6001	1e-05
17	20	Biased	0.59995	0.6	5e-05
18	20	Unbiased	0.60043	0.59985	-0.00058
19	20	Biased	0.60031	0.6003	-1e-05
20	50	Unbiased	0.60032	0.60051	0.00019
21	0	Correlation	0.60011	0.60014	3e-05
22	50	Unbiased	0.60001	0.60039	0.00038
23	0	Correlation	0.60008	0.60009	1e-05
24	20	Biased	0.60039	0.60041	2e-05
26	50	Biased	0.60007	0.6004	0.00033
27	30	Unbiased	0.60002	0.60007	5e-05
28	30	Biased	0.60037	0.60007	-0.0003
29	30	Unbiased	0.60041	0.60035	-6e-05
30	20	Biased	0.59982	0.59983	1e-05
31	30	Unbiased	0.60038	0.60039	1e-05
33	30	Biased	0.60004	0.60001	-3e-05
34	50	Unbiased	0.59998	0.6003	0.00032
35	20	Unbiased	0.60036	0.60025	-0.00011
41	30	Biased	0.60021	0.60049	0.00028

Test Statistics (V)

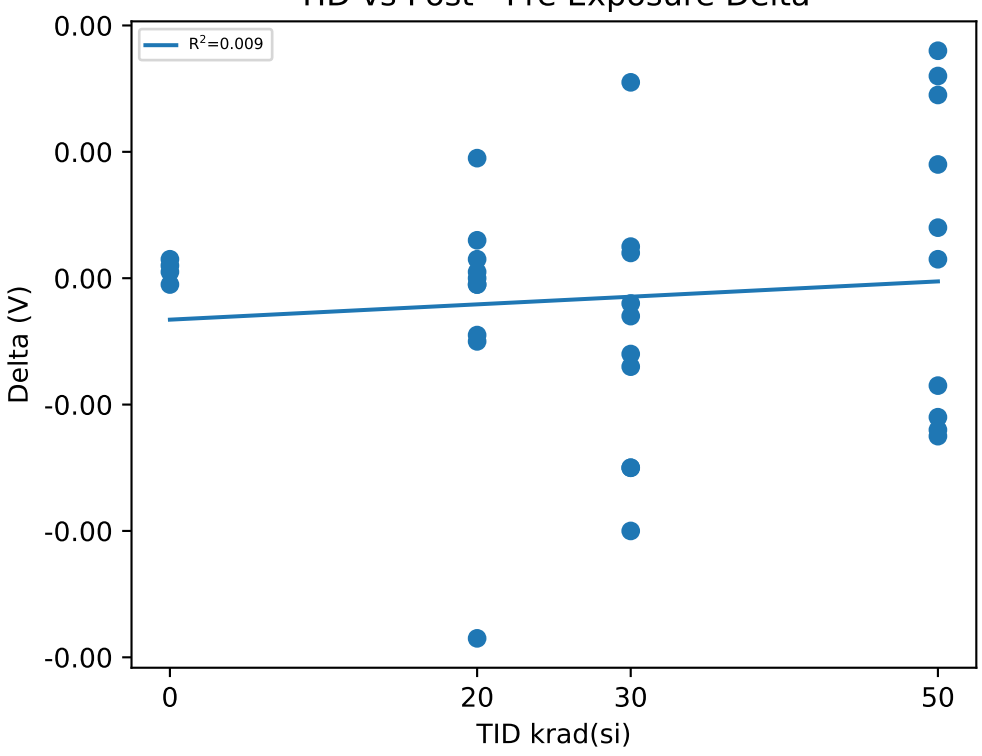
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.60008	0.60015	0.60031	0.00010739	0.60009	0.60017	0.60034	0.00011518	1e-05	2e-05	3e-05	1.1547e-05
20	0.59982	0.60015	0.60043	0.00024446	0.59983	0.6001	0.60041	0.00021944	-0.00058	-5.4e-05	0.00019	0.00020359
30	0.59984	0.60014	0.60043	0.00024837	0.59943	0.60004	0.60049	0.00036417	-0.00041	-0.0001	0.00028	0.00019972
50	0.59966	0.59998	0.60032	0.00021205	0.5994	0.60002	0.60051	0.00042191	-0.00026	4e-05	0.00038	0.00025604

Device Test: 19.73 VOLTAGE|VREF//12/12/0/1000/5/500kHz//@VREF_25C

TID vs Result Stats



TID vs Post - Pre Exposure Delta



Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

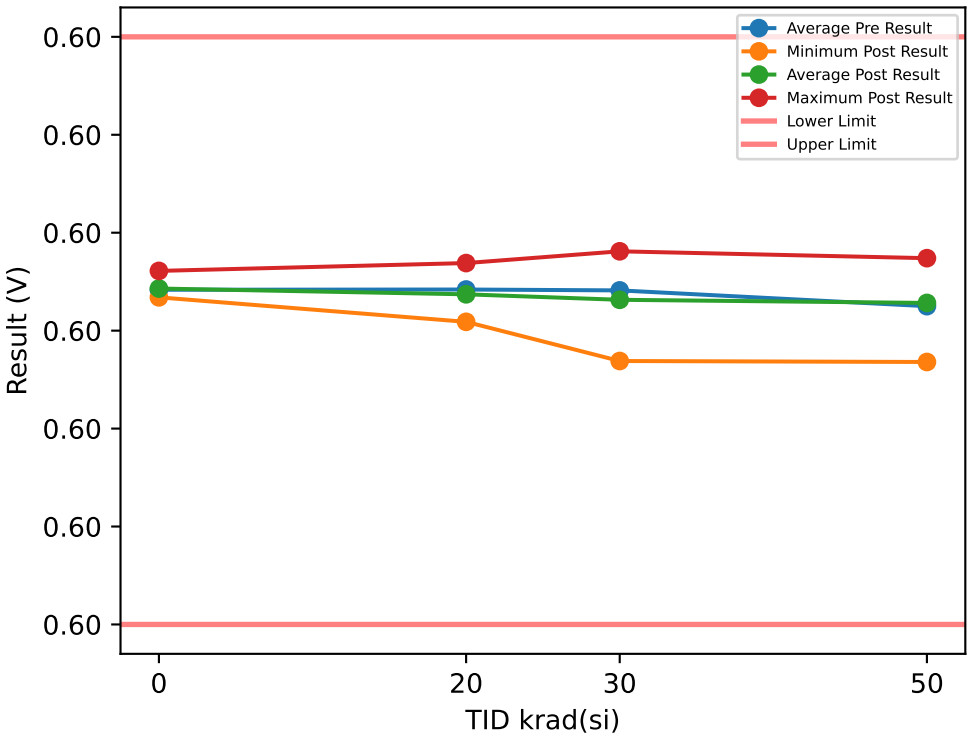
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	0.60025	0.60033	8e-05
2	20	Unbiased	0.60057	0.60057	0
3	50	Biased	0.59987	0.59962	-0.00025
4	30	Unbiased	0.6001	0.59996	-0.00014
5	50	Unbiased	0.60042	0.60045	3e-05
6	30	Biased	0.60006	0.59976	-0.0003
7	50	Biased	0.60011	0.59987	-0.00024
8	30	Unbiased	0.60004	0.59964	-0.0004
9	20	Unbiased	0.60004	0.60023	0.00019
10	50	Biased	0.59986	0.59964	-0.00022
11	30	Biased	0.60064	0.60052	-0.00012
12	0	Correlation	0.6003	0.60029	-1e-05
13	0	Correlation	0.60053	0.60055	2e-05
14	50	Unbiased	0.60012	0.59995	-0.00017
15	20	Biased	0.60019	0.60009	-0.0001
16	20	Unbiased	0.60032	0.60031	-1e-05
17	20	Biased	0.60015	0.60021	6e-05
18	20	Unbiased	0.60061	0.60004	-0.00057
19	20	Biased	0.60051	0.6005	-1e-05
20	50	Unbiased	0.60051	0.60069	0.00018
21	0	Correlation	0.60031	0.60034	3e-05
22	50	Unbiased	0.60024	0.6006	0.00036
23	0	Correlation	0.60029	0.6003	1e-05
24	20	Biased	0.6006	0.60063	3e-05
26	50	Biased	0.60029	0.60058	0.00029
27	30	Unbiased	0.60022	0.60027	5e-05
28	30	Biased	0.60059	0.60029	-0.0003
29	30	Unbiased	0.60061	0.60055	-6e-05
30	20	Biased	0.60002	0.60003	1e-05
31	30	Unbiased	0.60057	0.60061	4e-05
33	30	Biased	0.60024	0.6002	-4e-05
34	50	Unbiased	0.60021	0.60053	0.00032
35	20	Unbiased	0.60058	0.60049	-9e-05
41	30	Biased	0.60043	0.60074	0.00031

Test Statistics (V)

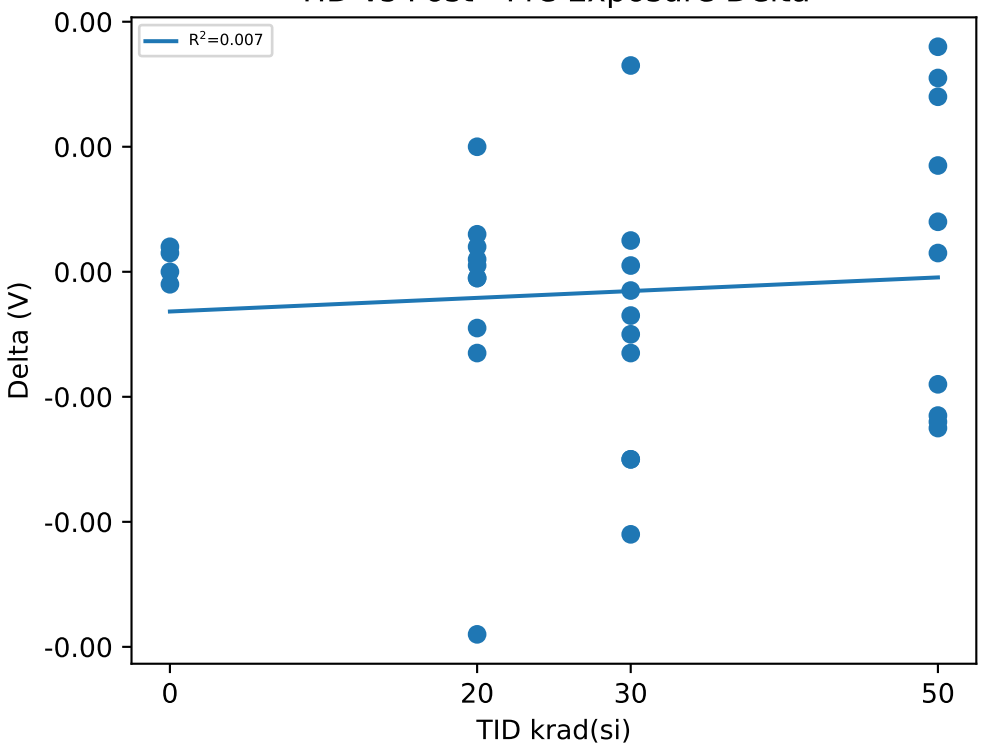
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.60029	0.60036	0.60053	0.00011529	0.60029	0.60037	0.60055	0.00012193	-1e-05	1.25e-05	3e-05	1.7078e-05
20	0.60002	0.60036	0.60061	0.00024214	0.60003	0.60031	0.60063	0.00022475	-0.00057	-4.9e-05	0.00019	0.00019997
30	0.60004	0.60035	0.60064	0.00024399	0.59964	0.60025	0.60074	0.00037017	-0.0004	-9.6e-05	0.00031	0.00020743
50	0.59986	0.60019	0.60051	0.00020933	0.59962	0.60023	0.60069	0.00041465	-0.00025	3.8e-05	0.00036	0.00024467

Device Test: 19.75 VOLTAGE|VREF//14/14/0/1000/5/500kHz//@VREF_25C

TID vs Result Stats



TID vs Post - Pre Exposure Delta



Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

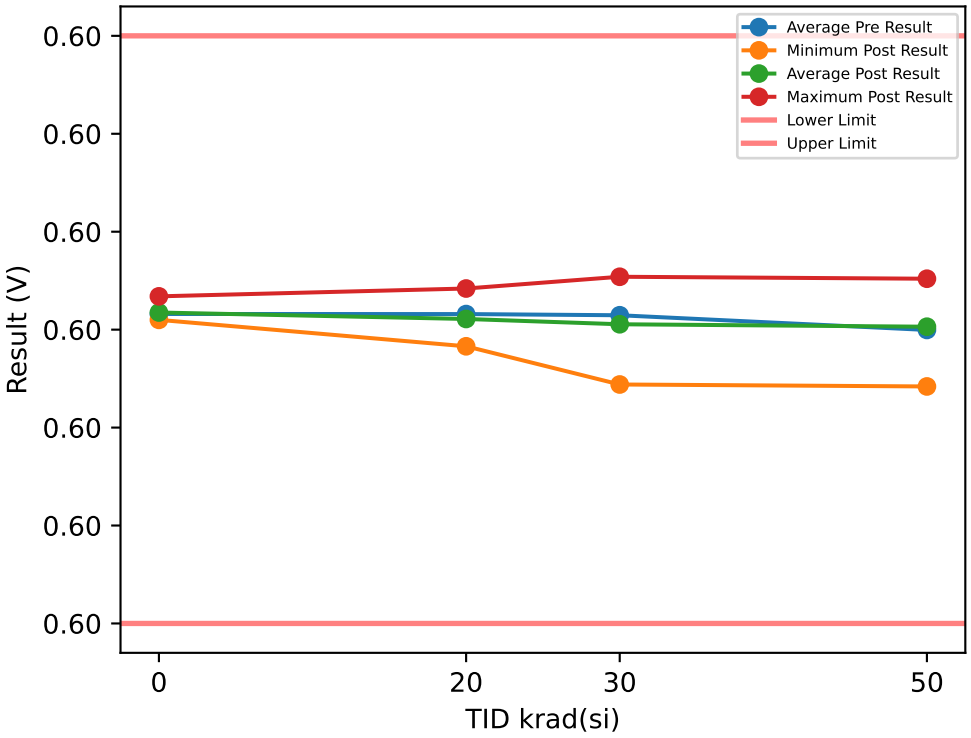
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	0.60031	0.60039	8e-05
2	20	Unbiased	0.60063	0.60064	1e-05
3	50	Biased	0.59993	0.59968	-0.00025
4	30	Unbiased	0.60016	0.60003	-0.00013
5	50	Unbiased	0.60049	0.60052	3e-05
6	30	Biased	0.60013	0.59983	-0.0003
7	50	Biased	0.60016	0.59992	-0.00024
8	30	Unbiased	0.60011	0.59969	-0.00042
9	20	Unbiased	0.6001	0.6003	0.0002
10	50	Biased	0.59992	0.59969	-0.00023
11	30	Biased	0.6007	0.6006	-0.0001
12	0	Correlation	0.60036	0.60034	-2e-05
13	0	Correlation	0.60058	0.60061	3e-05
14	50	Unbiased	0.60019	0.60001	-0.00018
15	20	Biased	0.60026	0.60013	-0.00013
16	20	Unbiased	0.60038	0.60037	-1e-05
17	20	Biased	0.60021	0.60027	6e-05
18	20	Unbiased	0.60067	0.60009	-0.00058
19	20	Biased	0.60057	0.60056	-1e-05
20	50	Unbiased	0.60057	0.60074	0.00017
21	0	Correlation	0.60037	0.60041	4e-05
22	50	Unbiased	0.6003	0.60066	0.00036
23	0	Correlation	0.60036	0.60036	0
24	20	Biased	0.60065	0.60069	4e-05
26	50	Biased	0.60035	0.60063	0.00028
27	30	Unbiased	0.60027	0.60032	5e-05
28	30	Biased	0.60065	0.60035	-0.0003
29	30	Unbiased	0.60068	0.60061	-7e-05
30	20	Biased	0.60008	0.6001	2e-05
31	30	Unbiased	0.60064	0.60065	1e-05
33	30	Biased	0.60029	0.60026	-3e-05
34	50	Unbiased	0.60028	0.60059	0.00031
35	20	Unbiased	0.60065	0.60056	-9e-05
41	30	Biased	0.60048	0.60081	0.00033

Test Statistics (V)

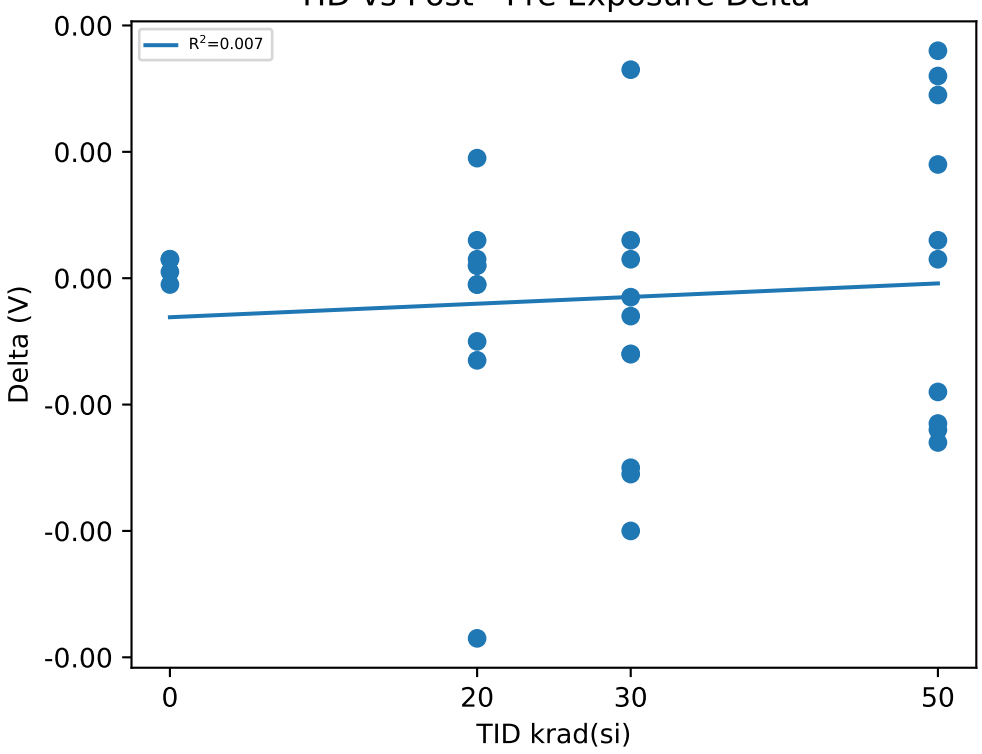
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.60036	0.60042	0.60058	0.00010844	0.60034	0.60043	0.60061	0.00012356	-2e-05	1.25e-05	4e-05	2.7538e-05
20	0.60008	0.60042	0.60067	0.00024134	0.60009	0.60037	0.60069	0.00022884	-0.00058	-4.9e-05	0.0002	0.00020637
30	0.60011	0.60041	0.6007	0.00024433	0.59969	0.60031	0.60081	0.00037071	-0.00042	-9.6e-05	0.00033	0.00021303
50	0.59992	0.60025	0.60057	0.00021082	0.59968	0.60028	0.60074	0.00041564	-0.00025	3.3e-05	0.00036	0.00024377

Device Test: 19.77 VOLTAGE|VREF//4.5/4.5/0/1000/4.5/1MHz//@VREF_25C

TID vs Result Stats



TID vs Post - Pre Exposure Delta



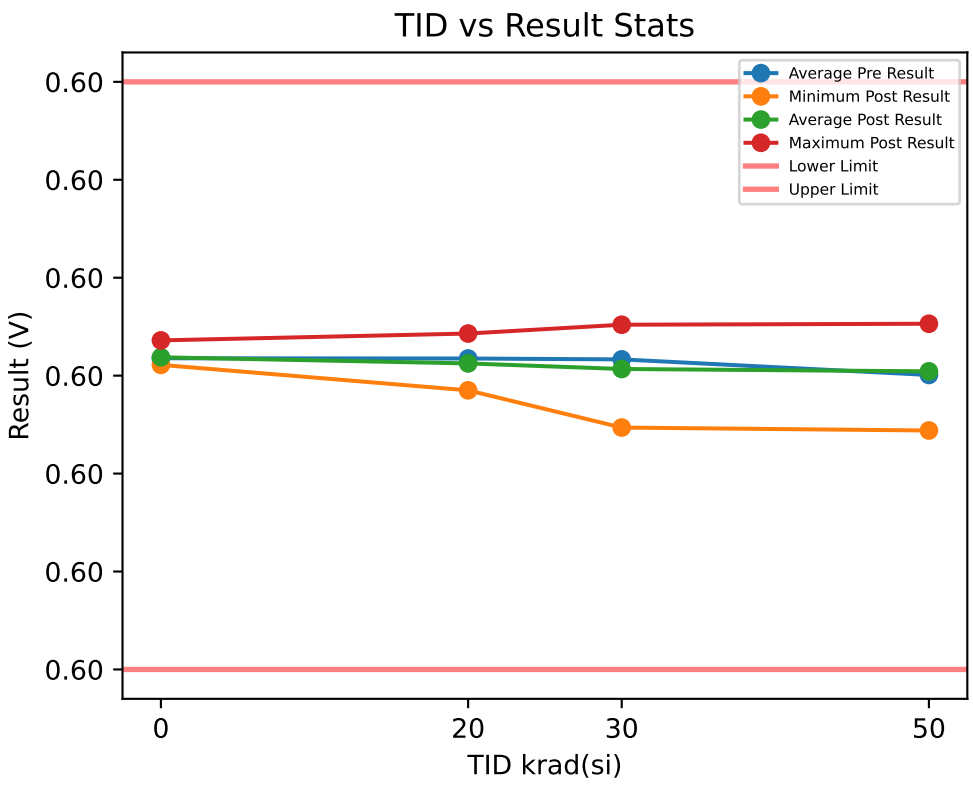
Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

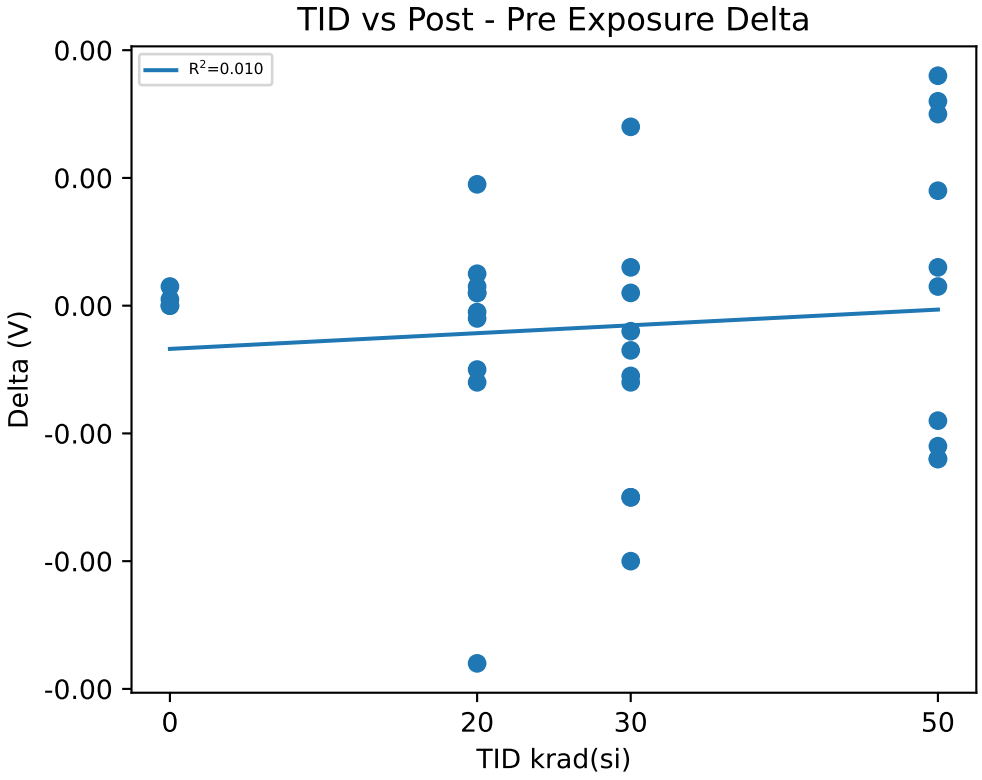
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	0.60007	0.60013	6e-05
2	20	Unbiased	0.60037	0.60039	2e-05
3	50	Biased	0.59968	0.59942	-0.00026
4	30	Unbiased	0.59988	0.59976	-0.00012
5	50	Unbiased	0.60024	0.60027	3e-05
6	30	Biased	0.59986	0.59956	-0.0003
7	50	Biased	0.59991	0.59967	-0.00024
8	30	Unbiased	0.59984	0.59944	-0.0004
9	20	Unbiased	0.59983	0.60002	0.00019
10	50	Biased	0.59967	0.59944	-0.00023
11	30	Biased	0.60043	0.60031	-0.00012
12	0	Correlation	0.60011	0.6001	-1e-05
13	0	Correlation	0.60031	0.60034	3e-05
14	50	Unbiased	0.59993	0.59975	-0.00018
15	20	Biased	0.60003	0.5999	-0.00013
16	20	Unbiased	0.60011	0.6001	-1e-05
17	20	Biased	0.59996	0.60002	6e-05
18	20	Unbiased	0.60042	0.59985	-0.00057
19	20	Biased	0.60032	0.60031	-1e-05
20	50	Unbiased	0.60034	0.60052	0.00018
21	0	Correlation	0.60012	0.60015	3e-05
22	50	Unbiased	0.60004	0.6004	0.00036
23	0	Correlation	0.6001	0.60011	1e-05
24	20	Biased	0.6004	0.60042	2e-05
26	50	Biased	0.6001	0.60039	0.00029
27	30	Unbiased	0.60002	0.60008	6e-05
28	30	Biased	0.60038	0.60007	-0.00031
29	30	Unbiased	0.60042	0.60036	-6e-05
30	20	Biased	0.5998	0.59983	3e-05
31	30	Unbiased	0.60038	0.60041	3e-05
33	30	Biased	0.60005	0.60002	-3e-05
34	50	Unbiased	0.59999	0.60031	0.00032
35	20	Unbiased	0.60035	0.60025	-0.0001
41	30	Biased	0.60021	0.60054	0.00033

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.6001	0.60016	0.60031	0.00010033	0.6001	0.60018	0.60034	0.0001121	-1e-05	1.5e-05	3e-05	1.9149e-05
20	0.5998	0.60016	0.60042	0.00024242	0.59983	0.60011	0.60042	0.00022123	-0.00057	-5e-05	0.00019	0.00020232
30	0.59984	0.60015	0.60043	0.00024509	0.59944	0.60006	0.60054	0.00036993	-0.0004	-9.2e-05	0.00033	0.00021296
50	0.59967	0.6	0.60034	0.00021448	0.59942	0.60003	0.60052	0.0004191	-0.00026	3.3e-05	0.00036	0.00024779

Device Test: 19.79 VOLTAGE|VREF//5/5/0/1000/5/1MHz//@VREF_25C





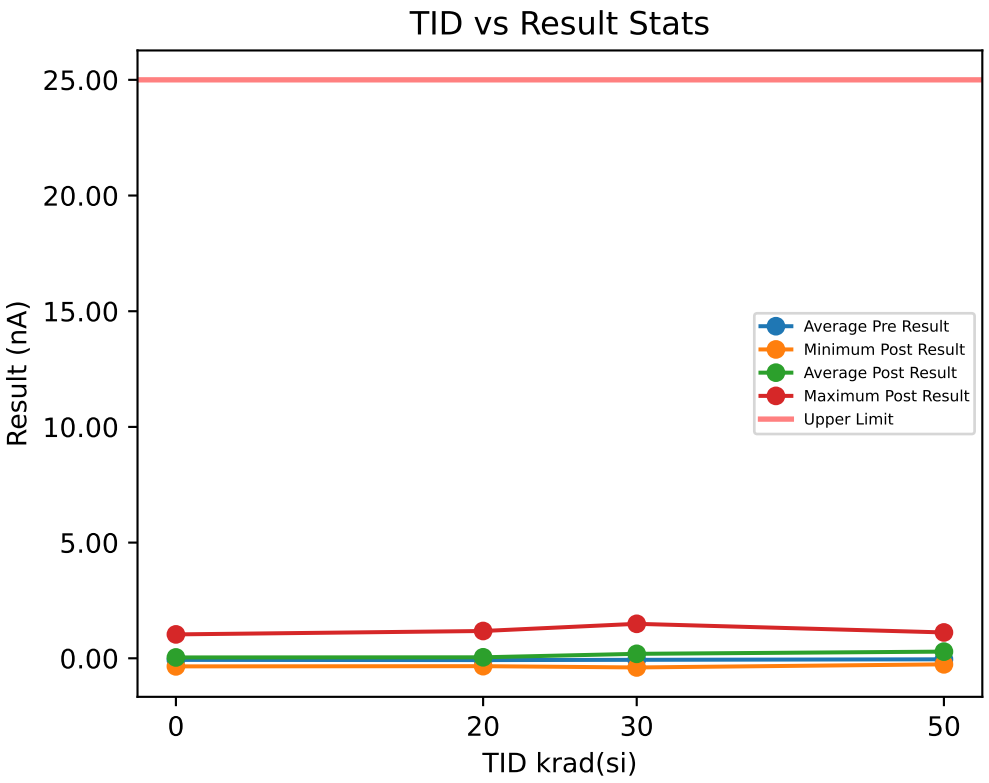
Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

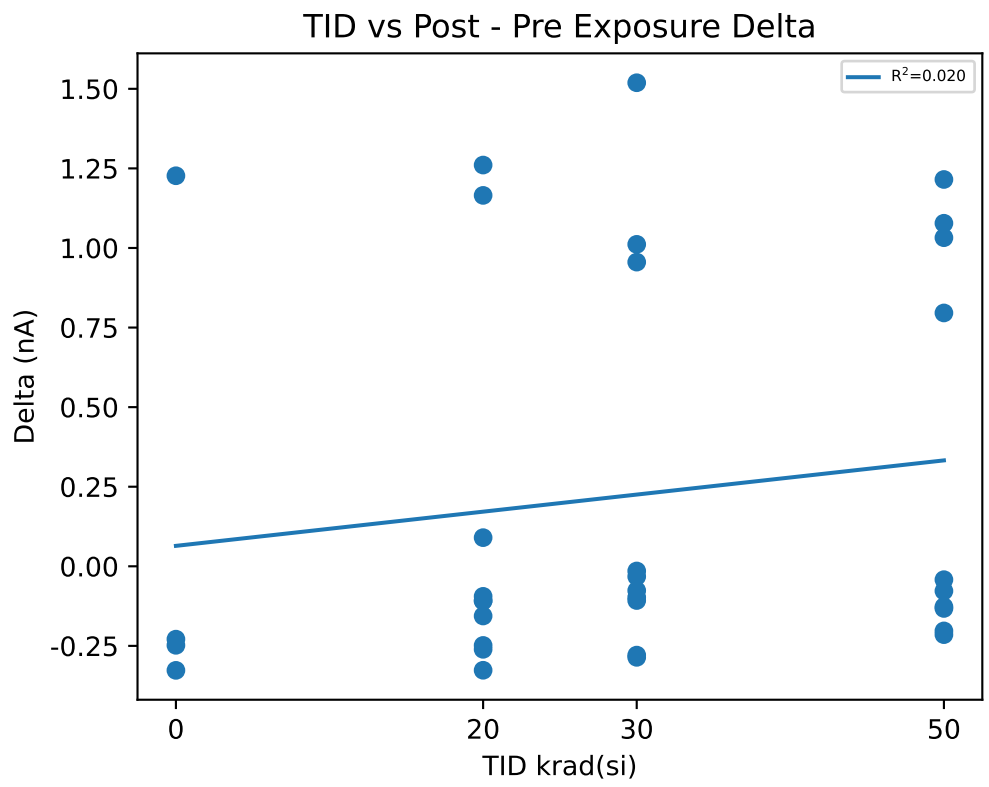
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	0.60009	0.60015	6e-05
2	20	Unbiased	0.60038	0.60041	3e-05
3	50	Biased	0.59968	0.59944	-0.00024
4	30	Unbiased	0.59989	0.59977	-0.00012
5	50	Unbiased	0.60025	0.60028	3e-05
6	30	Biased	0.59987	0.59957	-0.0003
7	50	Biased	0.59993	0.59969	-0.00024
8	30	Unbiased	0.59987	0.59947	-0.0004
9	20	Unbiased	0.59984	0.60003	0.00019
10	50	Biased	0.59968	0.59946	-0.00022
11	30	Biased	0.60045	0.60034	-0.00011
12	0	Correlation	0.60012	0.60012	0
13	0	Correlation	0.60035	0.60036	1e-05
14	50	Unbiased	0.59992	0.59974	-0.00018
15	20	Biased	0.60003	0.59991	-0.00012
16	20	Unbiased	0.60013	0.60012	-1e-05
17	20	Biased	0.59997	0.60002	5e-05
18	20	Unbiased	0.60044	0.59988	-0.00056
19	20	Biased	0.60034	0.60032	-2e-05
20	50	Unbiased	0.60035	0.60053	0.00018
21	0	Correlation	0.60013	0.60016	3e-05
22	50	Unbiased	0.60006	0.60042	0.00036
23	0	Correlation	0.60011	0.60011	0
24	20	Biased	0.60041	0.60043	2e-05
26	50	Biased	0.6001	0.6004	0.0003
27	30	Unbiased	0.60003	0.60009	6e-05
28	30	Biased	0.6004	0.6001	-0.0003
29	30	Unbiased	0.60044	0.60037	-7e-05
30	20	Biased	0.59983	0.59985	2e-05
31	30	Unbiased	0.6004	0.60042	2e-05
33	30	Biased	0.60007	0.60003	-4e-05
34	50	Unbiased	0.60001	0.60033	0.00032
35	20	Unbiased	0.60038	0.60028	-0.0001
41	30	Biased	0.60024	0.60052	0.00028

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.60011	0.60018	0.60035	0.00011529	0.60011	0.60019	0.60036	0.00011701	0	1e-05	3e-05	1.4142e-05
20	0.59983	0.60018	0.60044	0.00024337	0.59985	0.60013	0.60043	0.00022067	-0.00056	-5e-05	0.00019	0.00019827
30	0.59987	0.60017	0.60045	0.00024717	0.59947	0.60007	0.60052	0.00036374	-0.0004	-9.8e-05	0.00028	0.00019982
50	0.59968	0.60001	0.60035	0.00021664	0.59944	0.60004	0.60053	0.00041855	-0.00024	3.7e-05	0.00036	0.00024522

Device Test: 19.8 CURRENT|EA//5/5/0/0/5/500kHz//@EA_IB





Test Results (Upper Limit = 25.0 (nA))

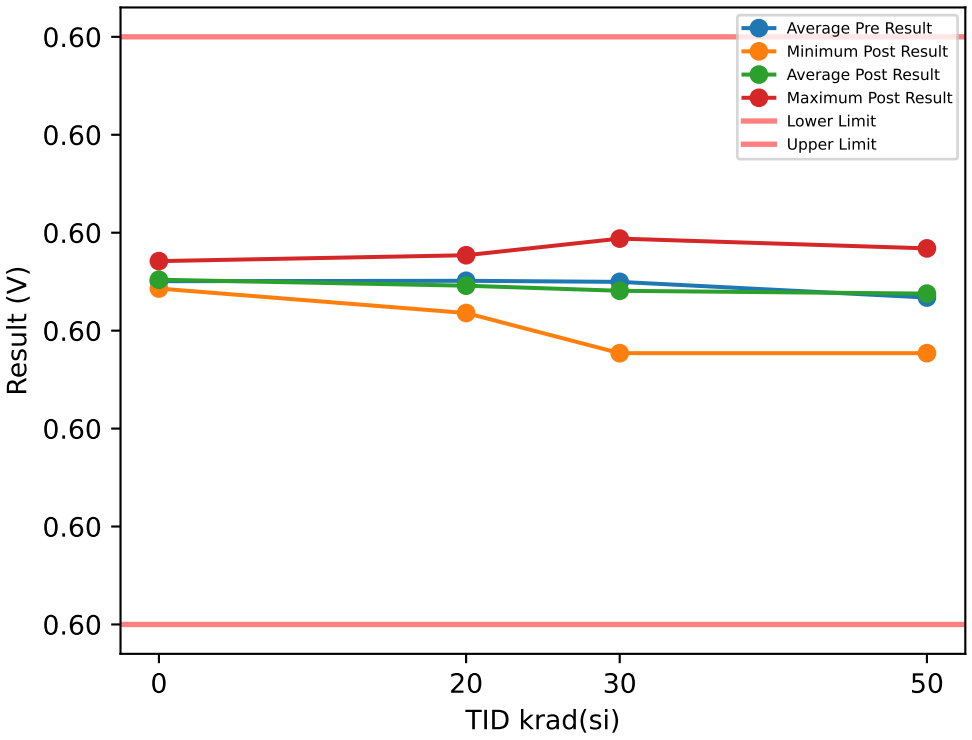
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	0.0776	0.8735	0.7959
2	20	Unbiased	-0.0808	1.1797	1.2605
3	50	Biased	-0.1167	0.961	1.0777
4	30	Unbiased	0.0553	-0.2237	-0.279
5	50	Unbiased	-0.0629	-0.1049	-0.042
6	30	Biased	-0.112	-0.1267	-0.0147
7	50	Biased	-0.098	1.1172	1.2152
8	30	Unbiased	-0.0726	-0.3586	-0.286
9	20	Unbiased	0.1089	-0.1519	-0.2608
10	50	Biased	-0.0371	-0.1642	-0.1271
11	30	Biased	-0.1511	-0.2485	-0.0974
12	0	Correlation	0.0054	-0.2235	-0.2289
13	0	Correlation	-0.1941	1.0328	1.2269
14	50	Unbiased	-0.0652	-0.1426	-0.0774
15	20	Biased	-0.0355	-0.1299	-0.0944
16	20	Unbiased	-0.0133	-0.3399	-0.3266
17	20	Biased	-0.191	-0.2993	-0.1083
18	20	Unbiased	-0.1245	-0.2806	-0.1561
19	20	Biased	-0.1199	1.0453	1.1652
20	50	Unbiased	0.0397	-0.0927	-0.1324
21	0	Correlation	-0.0223	-0.3492	-0.3269
22	50	Unbiased	-0.0465	-0.2612	-0.2147
23	0	Correlation	-0.0636	-0.3118	-0.2482
24	20	Biased	-0.0008	-0.2494	-0.2486
26	50	Biased	-0.0402	-0.2432	-0.203
27	30	Unbiased	-0.098	-0.1301	-0.0321
28	30	Biased	0.046	1.0016	0.9556
29	30	Unbiased	0.087	1.0984	1.0114
30	20	Biased	-0.0589	-0.1673	-0.1084
31	30	Unbiased	-0.3198	-0.396	-0.0762
33	30	Biased	-0.0692	-0.1767	-0.1075
34	50	Unbiased	-0.0901	0.9422	1.0323
35	20	Unbiased	-0.2667	-0.1767	0.09
41	30	Biased	-0.0292	1.4899	1.5191

Test Statistics (nA)

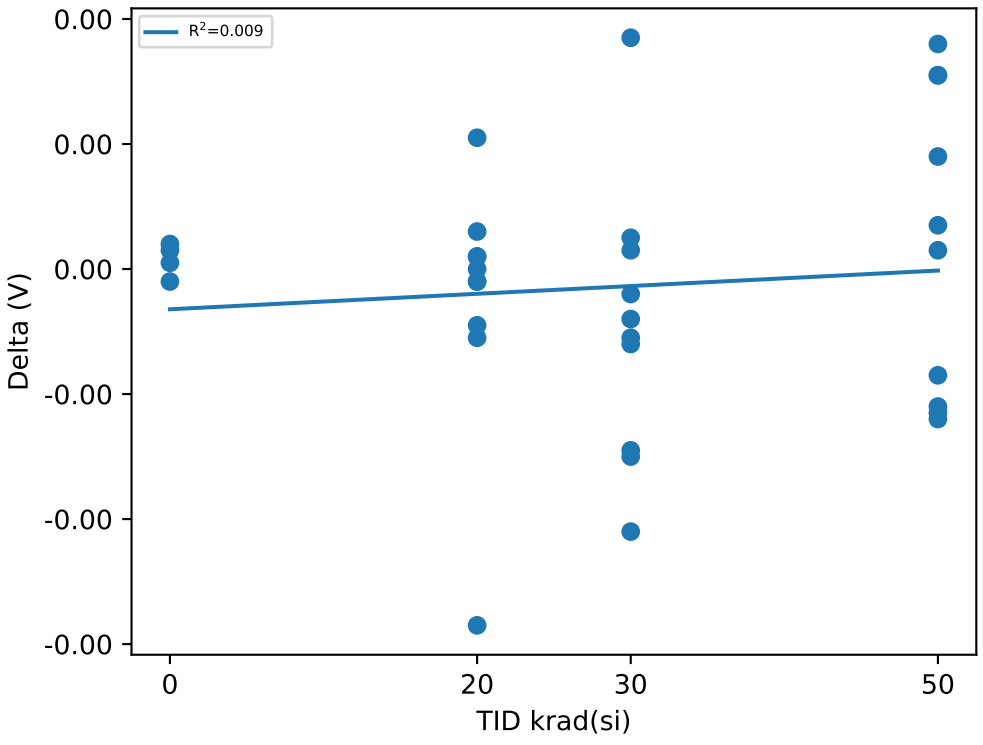
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.1941	-0.06865	0.0054	0.088308	-0.3492	0.037075	1.0328	0.66591	-0.3269	0.10572	1.2269	0.74865
20	-0.2667	-0.07825	0.1089	0.10517	-0.3399	0.043	1.1797	0.56873	-0.3266	0.12125	1.2605	0.58698
30	-0.3198	-0.06636	0.087	0.11873	-0.396	0.19296	1.4899	0.70856	-0.286	0.25932	1.5191	0.64627
50	-0.1167	-0.04394	0.0776	0.060547	-0.2612	0.28851	1.1172	0.59482	-0.2147	0.33245	1.2152	0.61108

Device Test: 19.81 VOLTAGE|VREF//12/12/0/1000/5/1MHz//@VREF_25C

TID vs Result Stats



TID vs Post - Pre Exposure Delta



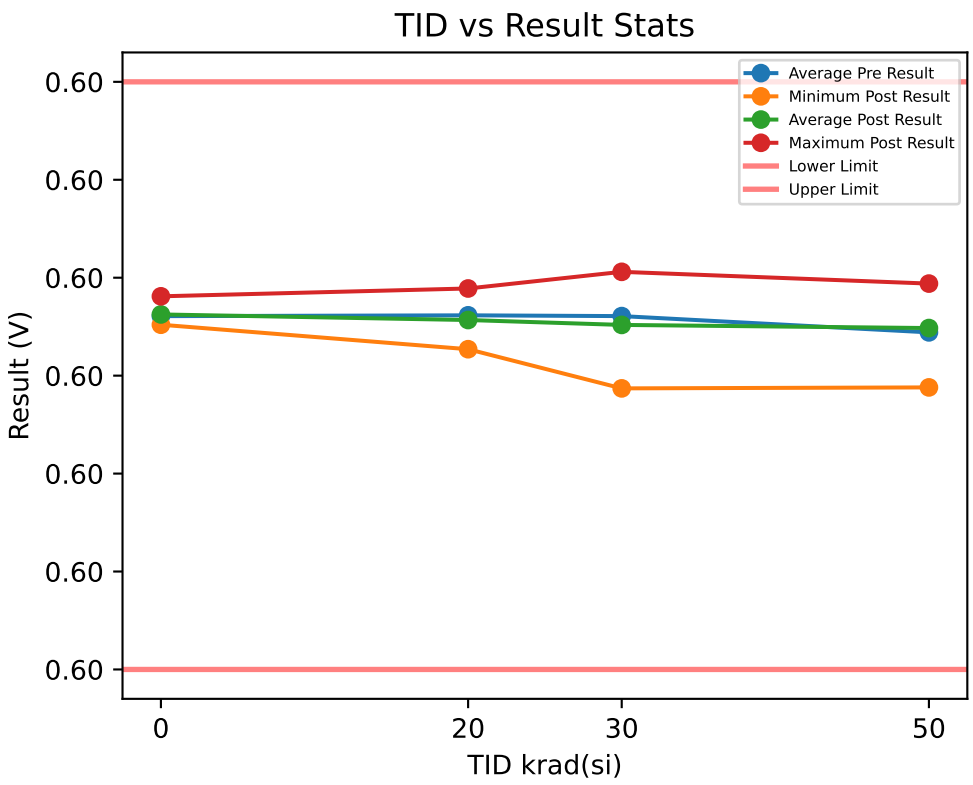
Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

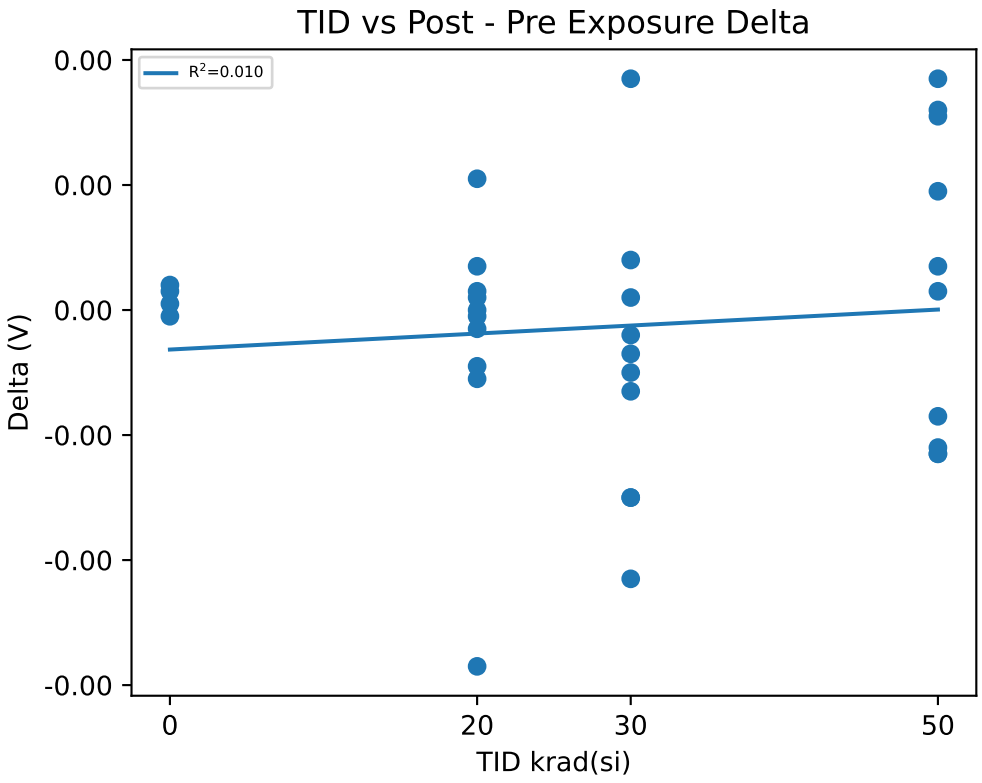
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	0.6004	0.60047	7e-05
2	20	Unbiased	0.60072	0.60072	0
3	50	Biased	0.60002	0.59978	-0.00024
4	30	Unbiased	0.60025	0.60013	-0.00012
5	50	Unbiased	0.60057	0.6006	3e-05
6	30	Biased	0.60022	0.59993	-0.00029
7	50	Biased	0.60025	0.60003	-0.00022
8	30	Unbiased	0.60019	0.59977	-0.00042
9	20	Unbiased	0.6002	0.60041	0.00021
10	50	Biased	0.6	0.59977	-0.00023
11	30	Biased	0.60079	0.60068	-0.00011
12	0	Correlation	0.60045	0.60043	-2e-05
13	0	Correlation	0.60068	0.60071	3e-05
14	50	Unbiased	0.60028	0.60011	-0.00017
15	20	Biased	0.60034	0.60023	-0.00011
16	20	Unbiased	0.60049	0.60047	-2e-05
17	20	Biased	0.6003	0.60036	6e-05
18	20	Unbiased	0.60075	0.60018	-0.00057
19	20	Biased	0.60064	0.60062	-2e-05
20	50	Unbiased	0.60066	0.60084	0.00018
21	0	Correlation	0.60045	0.60049	4e-05
22	50	Unbiased	0.6004	0.60076	0.00036
23	0	Correlation	0.60044	0.60045	1e-05
24	20	Biased	0.60075	0.60077	2e-05
26	50	Biased	0.60042	0.60073	0.00031
27	30	Unbiased	0.60036	0.60041	5e-05
28	30	Biased	0.60074	0.60044	-0.0003
29	30	Unbiased	0.60077	0.60069	-8e-05
30	20	Biased	0.60016	0.60018	2e-05
31	30	Unbiased	0.60071	0.60074	3e-05
33	30	Biased	0.60038	0.60034	-4e-05
34	50	Unbiased	0.60038	0.60069	0.00031
35	20	Unbiased	0.60074	0.60065	-9e-05
41	30	Biased	0.60057	0.60094	0.00037

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.60044	0.60051	0.60068	0.00011676	0.60043	0.60052	0.60071	0.0001291	-2e-05	1.5e-05	4e-05	2.6458e-05
20	0.60016	0.60051	0.60075	0.00024062	0.60018	0.60046	0.60077	0.00022303	-0.00057	-5e-05	0.00021	0.00020259
30	0.60019	0.6005	0.60079	0.00024371	0.59977	0.60041	0.60094	0.00037494	-0.00042	-9.1e-05	0.00037	0.00022173
50	0.6	0.60034	0.60066	0.00021086	0.59977	0.60038	0.60084	0.00041614	-0.00024	4e-05	0.00036	0.00024308

Device Test: 19.83 VOLTAGE|VREF//14/14/0/1000/5/1MHz//@VREF_25C





Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

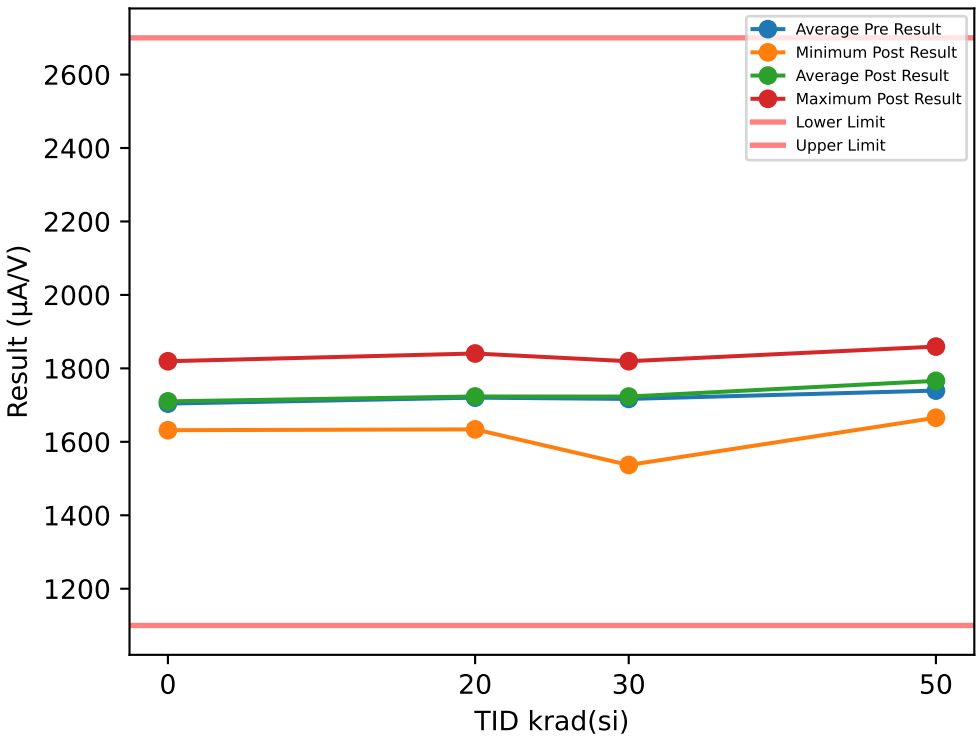
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	0.60049	0.60056	7e-05
2	20	Unbiased	0.60083	0.60083	0
3	50	Biased	0.60012	0.5999	-0.00022
4	30	Unbiased	0.60037	0.60024	-0.00013
5	50	Unbiased	0.60067	0.6007	3e-05
6	30	Biased	0.60034	0.60004	-0.0003
7	50	Biased	0.60035	0.60012	-0.00023
8	30	Unbiased	0.6003	0.59987	-0.00043
9	20	Unbiased	0.60032	0.60053	0.00021
10	50	Biased	0.60011	0.59988	-0.00023
11	30	Biased	0.6009	0.6008	-0.0001
12	0	Correlation	0.60053	0.60052	-1e-05
13	0	Correlation	0.60078	0.60081	3e-05
14	50	Unbiased	0.6004	0.60023	-0.00017
15	20	Biased	0.60044	0.60033	-0.00011
16	20	Unbiased	0.6006	0.60057	-3e-05
17	20	Biased	0.60039	0.60046	7e-05
18	20	Unbiased	0.60084	0.60027	-0.00057
19	20	Biased	0.60074	0.60073	-1e-05
20	50	Unbiased	0.60075	0.60094	0.00019
21	0	Correlation	0.60057	0.60061	4e-05
22	50	Unbiased	0.60051	0.60088	0.00037
23	0	Correlation	0.60055	0.60056	1e-05
24	20	Biased	0.60087	0.60089	2e-05
26	50	Biased	0.60052	0.60084	0.00032
27	30	Unbiased	0.60045	0.60053	8e-05
28	30	Biased	0.60085	0.60055	-0.0003
29	30	Unbiased	0.60088	0.60081	-7e-05
30	20	Biased	0.60027	0.6003	3e-05
31	30	Unbiased	0.60082	0.60084	2e-05
33	30	Biased	0.60048	0.60044	-4e-05
34	50	Unbiased	0.6005	0.60081	0.00031
35	20	Unbiased	0.60086	0.60077	-9e-05
41	30	Biased	0.60069	0.60106	0.00037

Test Statistics (V)

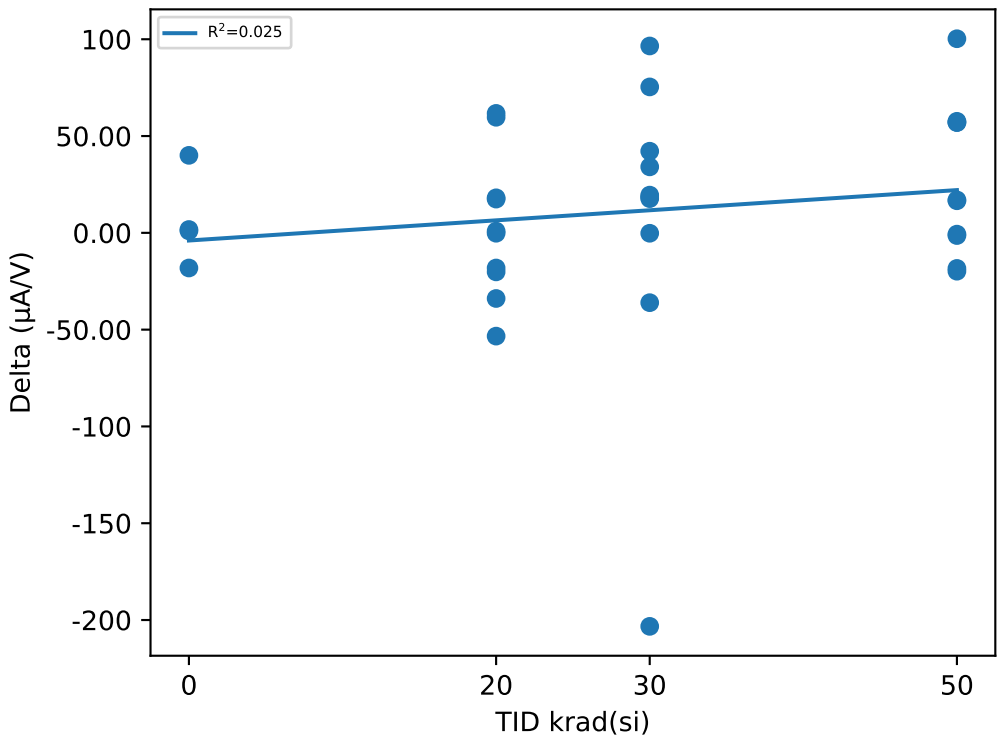
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.60053	0.60061	0.60078	0.00011615	0.60052	0.60062	0.60081	0.00012871	-1e-05	1.75e-05	4e-05	2.2174e-05
20	0.60027	0.60062	0.60087	0.00024153	0.60027	0.60057	0.60089	0.00022846	-0.00057	-4.8e-05	0.00021	0.00020368
30	0.6003	0.60061	0.6009	0.00024362	0.59987	0.60052	0.60106	0.00037935	-0.00043	-9e-05	0.00037	0.00022632
50	0.60011	0.60044	0.60075	0.00020746	0.59988	0.60049	0.60094	0.0004154	-0.00023	4.4e-05	0.00037	0.00024518

Device Test: 19.9 LEVEL|TRANSCONDUCTANCE//12/12/0/0/5/500kHz//@EA_GM

TID vs Result Stats



TID vs Post - Pre Exposure Delta



Test Results (Lower Limit = 1100.0, Upper Limit = 2700.0 (µA/V))

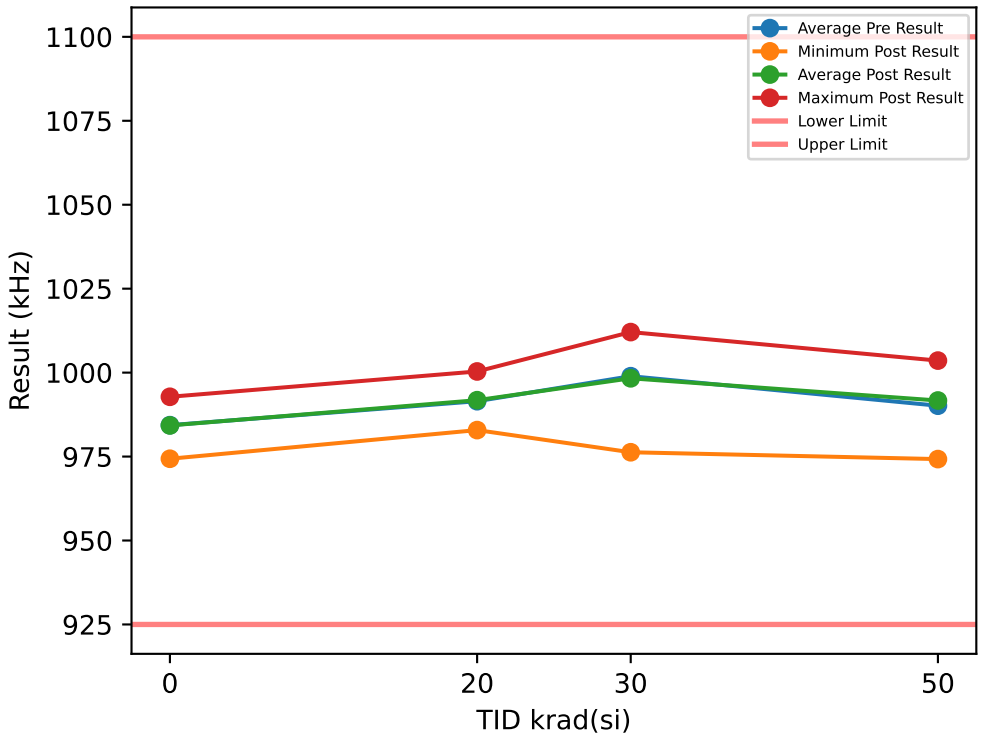
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	1720.8	1719.4	-1.3932
2	20	Unbiased	1759.3	1776.7	17.429
3	50	Biased	1649.1	1665.6	16.568
4	30	Unbiased	1703.7	1779	75.379
5	50	Unbiased	1702.5	1759.4	56.962
6	30	Biased	1721.4	1685.3	-36.072
7	50	Biased	1860	1859.3	-0.67
8	30	Unbiased	1740.7	1740.5	-0.2167
9	20	Unbiased	1684.5	1685.4	0.8885
10	50	Biased	1798.8	1779	-19.817
11	30	Biased	1683.8	1703.3	19.487
12	0	Correlation	1779.4	1819.4	40.031
13	0	Correlation	1649.8	1631.6	-18.155
14	50	Unbiased	1740.1	1840.4	100.26
15	20	Biased	1738.7	1685.3	-53.35
16	20	Unbiased	1634.1	1633.9	-0.2069
17	20	Biased	1739.5	1799.2	59.701
18	20	Unbiased	1778.8	1840.5	61.704
19	20	Biased	1777.3	1757.2	-20.169
20	50	Unbiased	1722	1779.1	57.072
21	0	Correlation	1720.8	1721.8	1.0154
22	50	Unbiased	1721.4	1779.1	57.619
23	0	Correlation	1666.2	1668	1.7228
24	20	Biased	1703.7	1685.5	-18.16
26	50	Biased	1740.1	1721.8	-18.376
27	30	Unbiased	1777.3	1819.5	42.164
28	30	Biased	1799.4	1817.1	17.676
29	30	Unbiased	1667	1701.1	34.083
30	20	Biased	1685.2	1703.3	18.092
31	30	Unbiased	1632.2	1650.8	18.517
33	30	Biased	1702.4	1799	96.523
34	50	Unbiased	1740.1	1757.2	17.004
35	20	Unbiased	1701.7	1667.8	-33.909
41	30	Biased	1740.2	1536.9	-203.27

Test Statistics (µA/V)

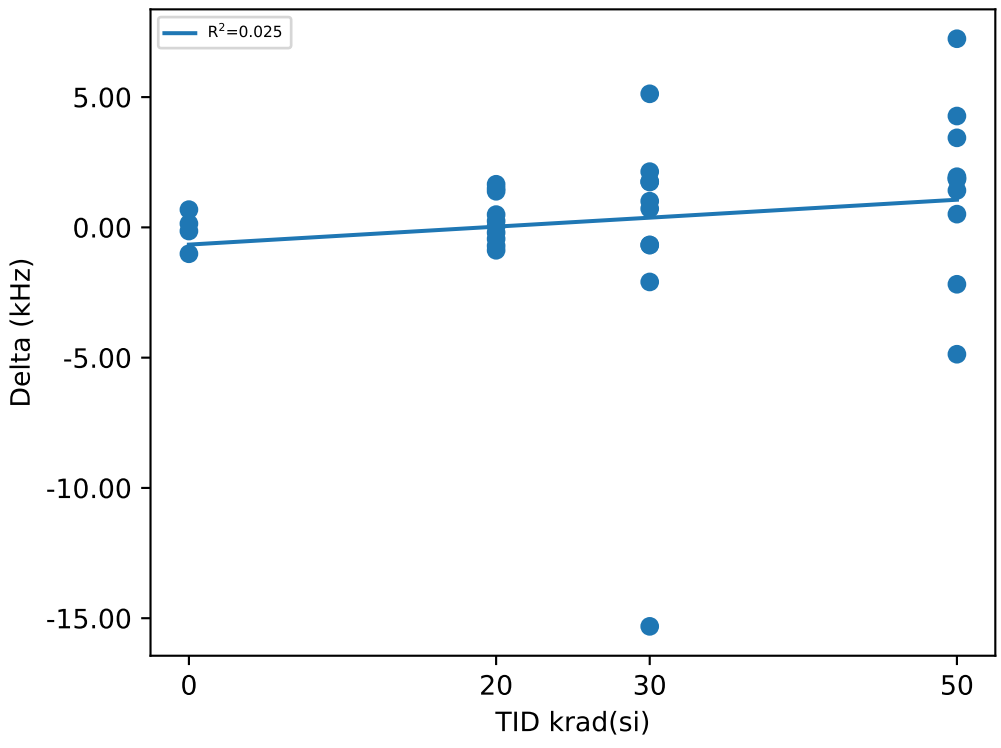
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1649.8	1704	1779.4	58.673	1631.6	1710.2	1819.4	81.685	-18.155	6.1536	40.031	24.39
20	1634.1	1720.3	1778.8	46.499	1633.9	1723.5	1840.5	66.051	-53.35	3.202	61.704	37.466
30	1632.2	1716.8	1799.4	50.246	1536.9	1723.2	1819.5	87.88	-203.27	6.427	96.523	82.449
50	1649.1	1739.5	1860	56.34	1665.6	1766	1859.3	56.842	-19.817	26.523	100.26	39.632

Device Test: 20.101 LEVEL|FREQ/RT/14/14/0/1000/5/1MHz//@FSW_EXT_RT_D

TID vs Result Stats



TID vs Post - Pre Exposure Delta



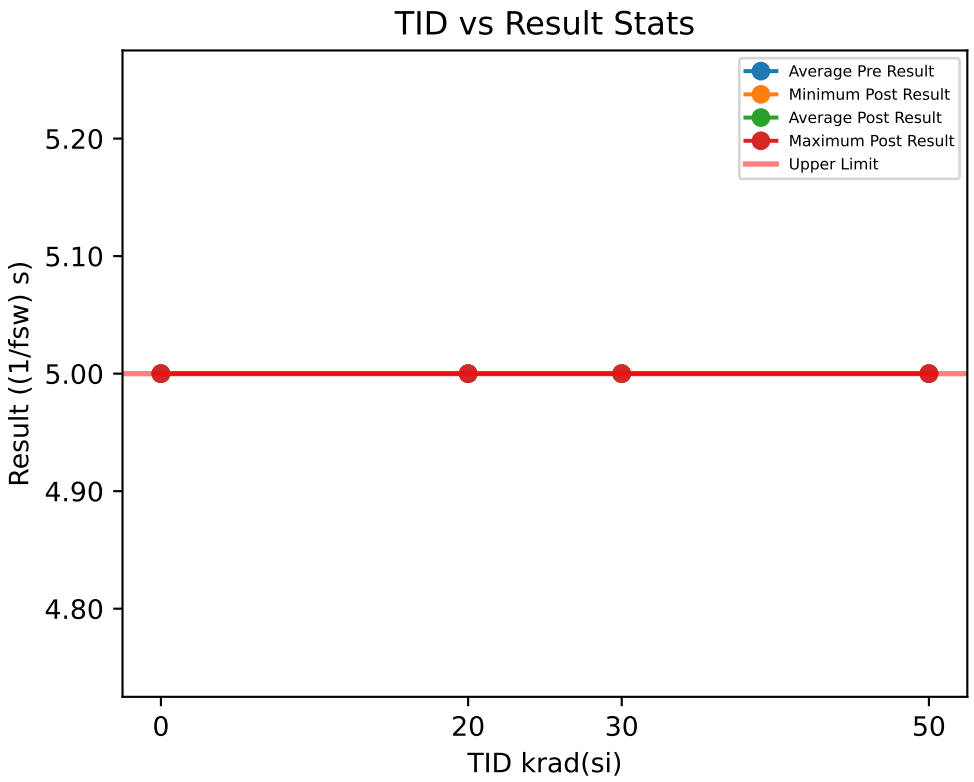
Test Results (Lower Limit = 925.0, Upper Limit = 1100.0 (kHz))

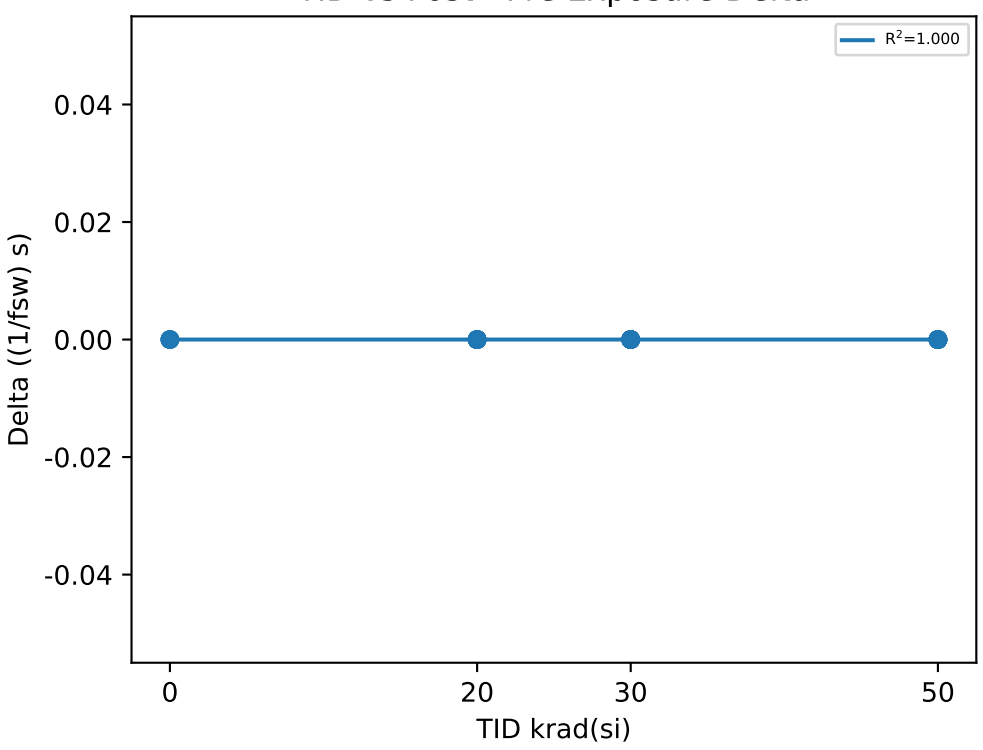
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	982.96	984.81	1.846
2	20	Unbiased	994.78	994.58	-0.2011
3	50	Biased	1001.1	1003.1	1.9443
4	30	Unbiased	1003.7	1005.8	2.1392
5	50	Unbiased	979.12	974.25	-4.8683
6	30	Biased	990.7	995.83	5.1265
7	50	Biased	993.53	994.95	1.4184
8	30	Unbiased	993.32	991.22	-2.0941
9	20	Unbiased	987.35	988.85	1.4949
10	50	Biased	995.14	999.42	4.2738
11	30	Biased	1004	1005.8	1.7619
12	0	Correlation	974.21	974.35	0.1429
13	0	Correlation	978.7	979.38	0.6815
14	50	Unbiased	1003.1	1003.6	0.5083
15	20	Biased	991.3	991.55	0.2442
16	20	Unbiased	983.16	984.55	1.3854
17	20	Biased	998.68	997.8	-0.8793
18	20	Unbiased	988.57	987.86	-0.7072
19	20	Biased	1000.3	1000.3	0.0413
20	50	Unbiased	987.92	985.73	-2.1835
21	0	Correlation	991.57	990.55	-1.0126
22	50	Unbiased	985.98	987.85	1.8743
23	0	Correlation	992.94	992.8	-0.1403
24	20	Biased	996.21	995.77	-0.4407
26	50	Biased	989.38	992.82	3.4368
27	30	Unbiased	987.56	988.28	0.7193
28	30	Biased	1004.5	1006.2	1.7401
29	30	Unbiased	1012.8	1012.1	-0.6789
30	20	Biased	981.23	982.88	1.655
31	30	Unbiased	1004.7	1004	-0.6741
33	30	Biased	996.59	997.59	1.006
34	50	Unbiased	983.23	990.47	7.2401
35	20	Unbiased	993.24	993.73	0.4906
41	30	Biased	991.6	976.28	-15.312

Test Statistics (kHz)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	974.21	984.35	992.94	9.3229	974.35	984.27	992.8	8.8436	-1.0126	-0.082125	0.6815	0.7078
20	981.23	991.48	1000.3	6.377	982.88	991.79	1000.3	5.7031	-0.8793	0.30831	1.655	0.92811
30	987.56	998.93	1012.8	8.1017	976.28	998.31	1012.1	10.744	-15.312	-0.62666	5.1265	5.5213
50	979.12	990.15	1003.1	7.9483	974.25	991.7	1003.6	9.1056	-4.8683	1.549	7.2401	3.3323

Device Test: 20.112 FREQ|DETECTION/SYNC/4.5/4.5/0/0/4.5/100kHz//@T_SYNC_DET





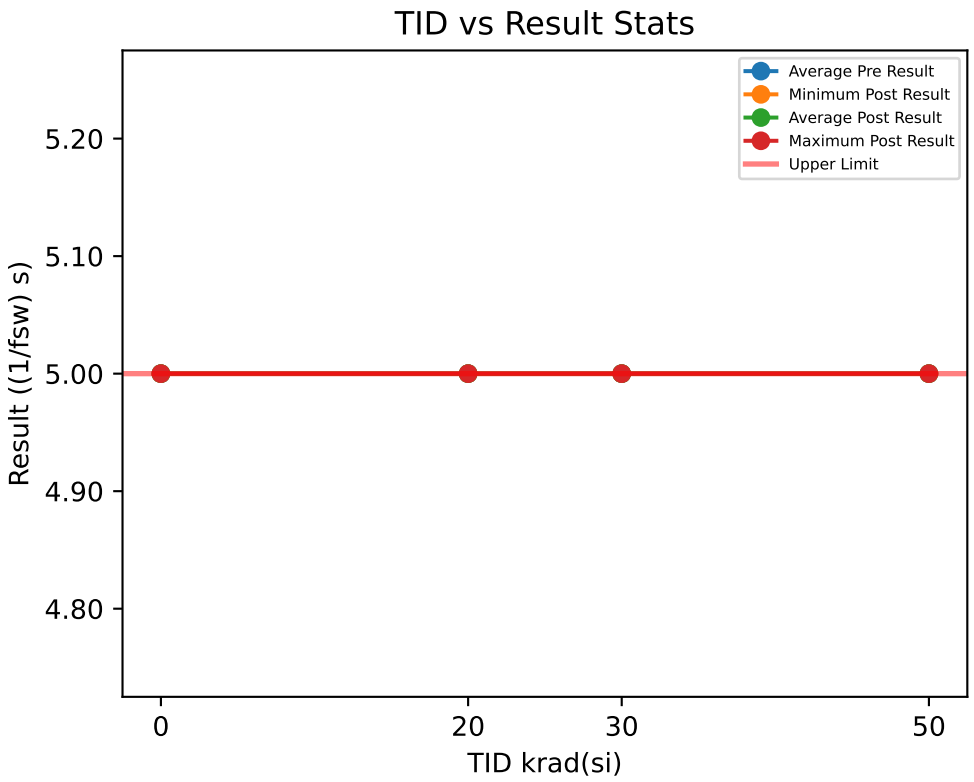
Test Results (Upper Limit = 5.0 ((1/fsw) s))

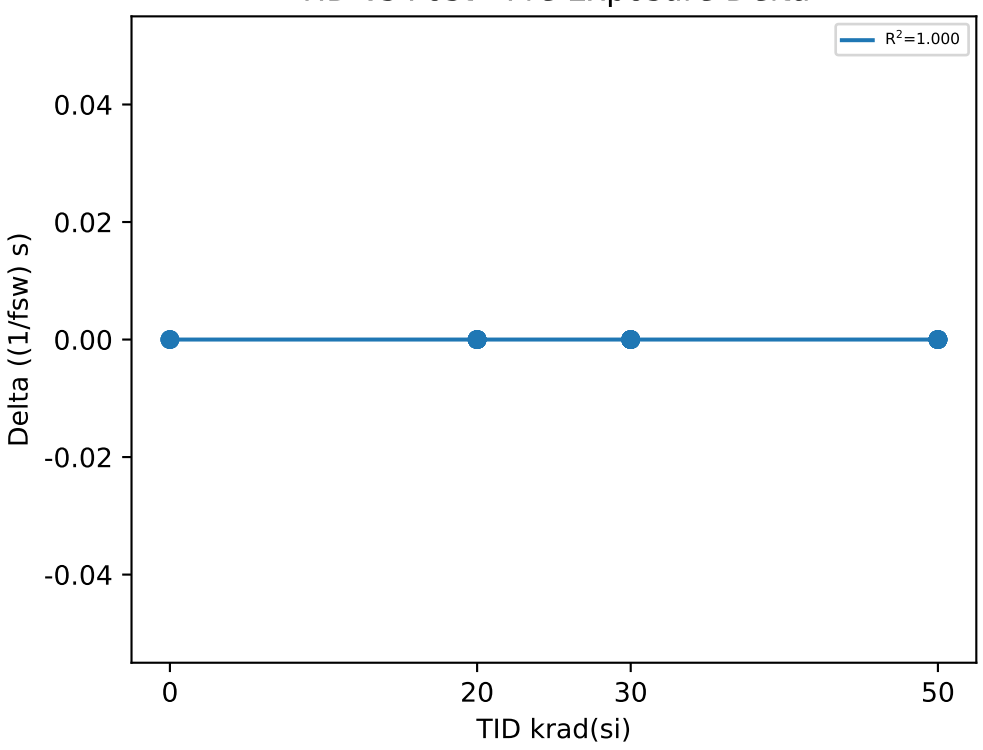
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	5	5	0
2	20	Unbiased	5	5	0
3	50	Biased	5	5	0
4	30	Unbiased	5	5	0
5	50	Unbiased	5	5	0
6	30	Biased	5	5	0
7	50	Biased	5	5	0
8	30	Unbiased	5	5	0
9	20	Unbiased	5	5	0
10	50	Biased	5	5	0
11	30	Biased	5	5	0
12	0	Correlation	5	5	0
13	0	Correlation	5	5	0
14	50	Unbiased	5	5	0
15	20	Biased	5	5	0
16	20	Unbiased	5	5	0
17	20	Biased	5	5	0
18	20	Unbiased	5	5	0
19	20	Biased	5	5	0
20	50	Unbiased	5	5	0
21	0	Correlation	5	5	0
22	50	Unbiased	5	5	0
23	0	Correlation	5	5	0
24	20	Biased	5	5	0
26	50	Biased	5	5	0
27	30	Unbiased	5	5	0
28	30	Biased	5	5	0
29	30	Unbiased	5	5	0
30	20	Biased	5	5	0
31	30	Unbiased	5	5	0
33	30	Biased	5	5	0
34	50	Unbiased	5	5	0
35	20	Unbiased	5	5	0
41	30	Biased	5	5	0

Test Statistics ((1/fsw) s)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5	5	5	0	5	5	5	0	0	0	0	0
20	5	5	5	0	5	5	5	0	0	0	0	0
30	5	5	5	0	5	5	5	0	0	0	0	0
50	5	5	5	0	5	5	5	0	0	0	0	0

Device Test: 20.114 FREQ|DETECTION/SYNC/5/5/0/0/5/100kHz//@T_SYNC_DET





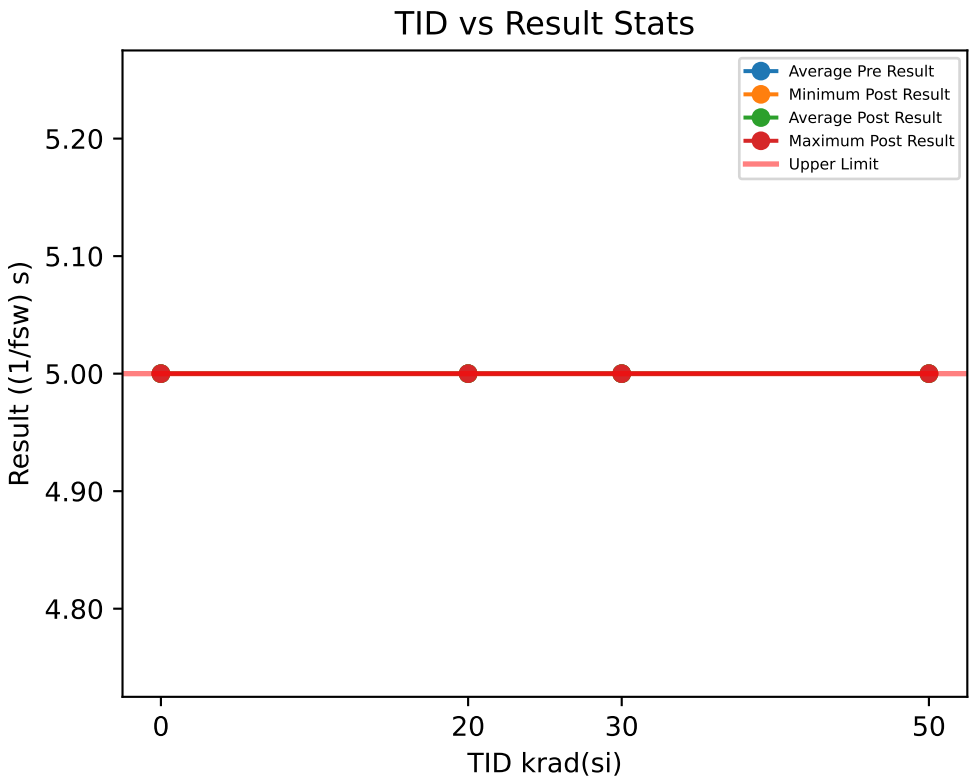
Test Results (Upper Limit = 5.0 ((1/fsw) s))

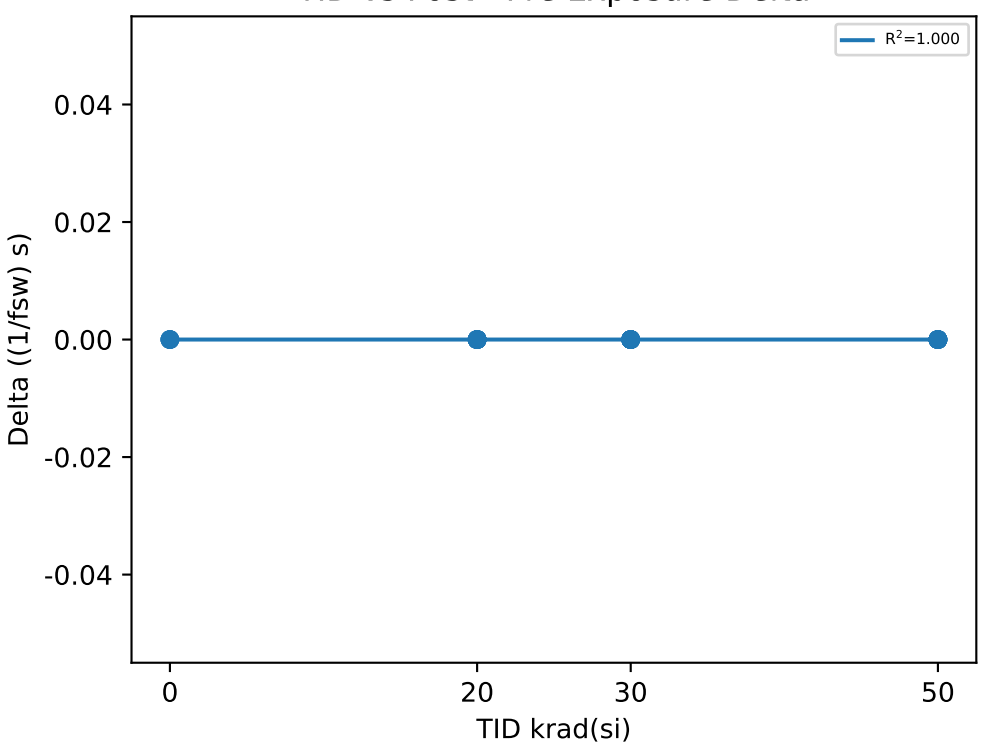
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	5	5	0
2	20	Unbiased	5	5	0
3	50	Biased	5	5	0
4	30	Unbiased	5	5	0
5	50	Unbiased	5	5	0
6	30	Biased	5	5	0
7	50	Biased	5	5	0
8	30	Unbiased	5	5	0
9	20	Unbiased	5	5	0
10	50	Biased	5	5	0
11	30	Biased	5	5	0
12	0	Correlation	5	5	0
13	0	Correlation	5	5	0
14	50	Unbiased	5	5	0
15	20	Biased	5	5	0
16	20	Unbiased	5	5	0
17	20	Biased	5	5	0
18	20	Unbiased	5	5	0
19	20	Biased	5	5	0
20	50	Unbiased	5	5	0
21	0	Correlation	5	5	0
22	50	Unbiased	5	5	0
23	0	Correlation	5	5	0
24	20	Biased	5	5	0
26	50	Biased	5	5	0
27	30	Unbiased	5	5	0
28	30	Biased	5	5	0
29	30	Unbiased	5	5	0
30	20	Biased	5	5	0
31	30	Unbiased	5	5	0
33	30	Biased	5	5	0
34	50	Unbiased	5	5	0
35	20	Unbiased	5	5	0
41	30	Biased	5	5	0

Test Statistics ((1/fsw) s)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5	5	5	0	5	5	5	0	0	0	0	0
20	5	5	5	0	5	5	5	0	0	0	0	0
30	5	5	5	0	5	5	5	0	0	0	0	0
50	5	5	5	0	5	5	5	0	0	0	0	0

Device Test: 20.116 FREQ|DETECTION/SYNC/12/12/0/0/5/100kHz//@T_SYNC_DET





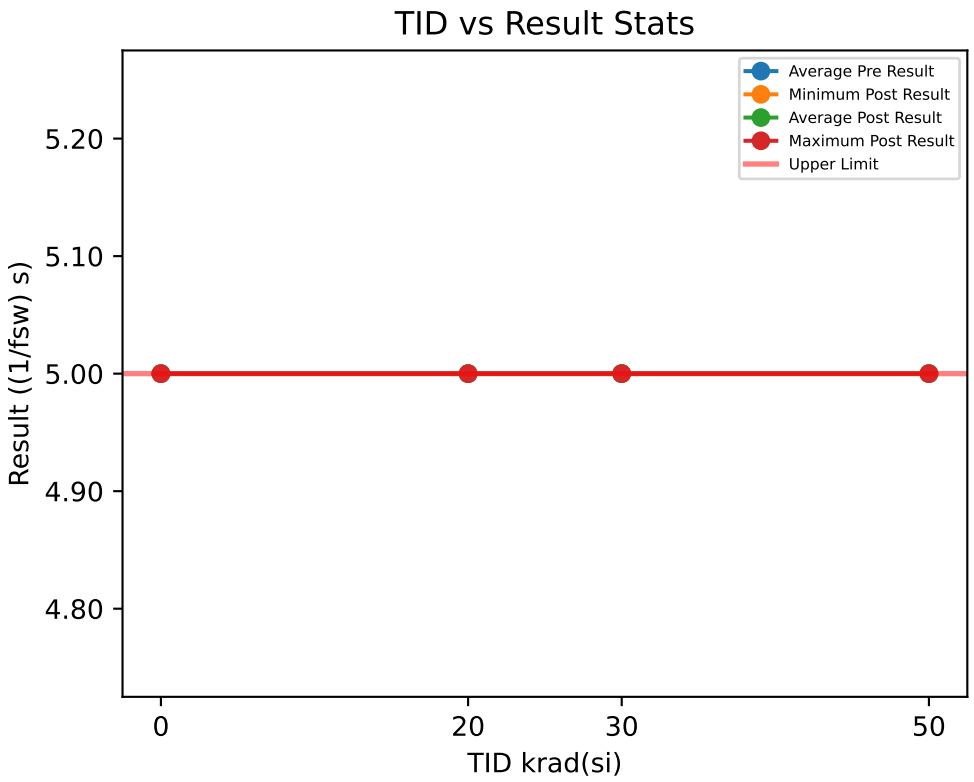
Test Results (Upper Limit = 5.0 ((1/fsw) s))

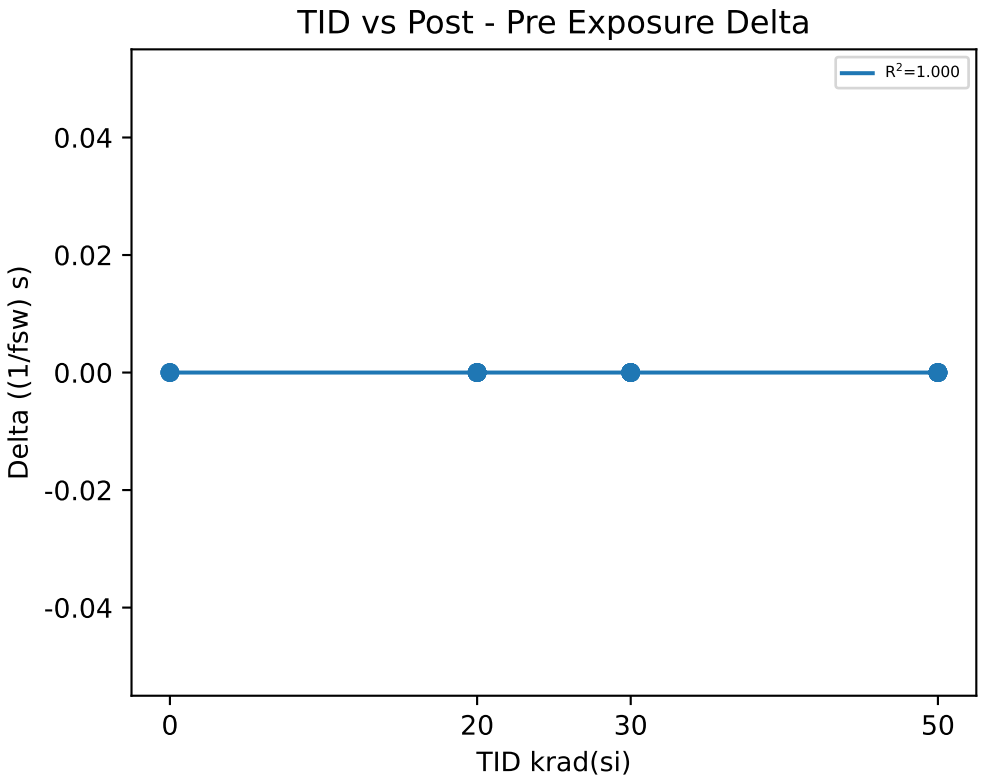
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	5	5	0
2	20	Unbiased	5	5	0
3	50	Biased	5	5	0
4	30	Unbiased	5	5	0
5	50	Unbiased	5	5	0
6	30	Biased	5	5	0
7	50	Biased	5	5	0
8	30	Unbiased	5	5	0
9	20	Unbiased	5	5	0
10	50	Biased	5	5	0
11	30	Biased	5	5	0
12	0	Correlation	5	5	0
13	0	Correlation	5	5	0
14	50	Unbiased	5	5	0
15	20	Biased	5	5	0
16	20	Unbiased	5	5	0
17	20	Biased	5	5	0
18	20	Unbiased	5	5	0
19	20	Biased	5	5	0
20	50	Unbiased	5	5	0
21	0	Correlation	5	5	0
22	50	Unbiased	5	5	0
23	0	Correlation	5	5	0
24	20	Biased	5	5	0
26	50	Biased	5	5	0
27	30	Unbiased	5	5	0
28	30	Biased	5	5	0
29	30	Unbiased	5	5	0
30	20	Biased	5	5	0
31	30	Unbiased	5	5	0
33	30	Biased	5	5	0
34	50	Unbiased	5	5	0
35	20	Unbiased	5	5	0
41	30	Biased	5	5	0

Test Statistics ((1/fsw) s)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5	5	5	0	5	5	5	0	0	0	0	0
20	5	5	5	0	5	5	5	0	0	0	0	0
30	5	5	5	0	5	5	5	0	0	0	0	0
50	5	5	5	0	5	5	5	0	0	0	0	0

Device Test: 20.118 FREQ|DETECTION/SYNC/14/14/0/0/5/100kHz//@T_SYNC_DET





Test Results (Upper Limit = 5.0 ((1/fsw) s))

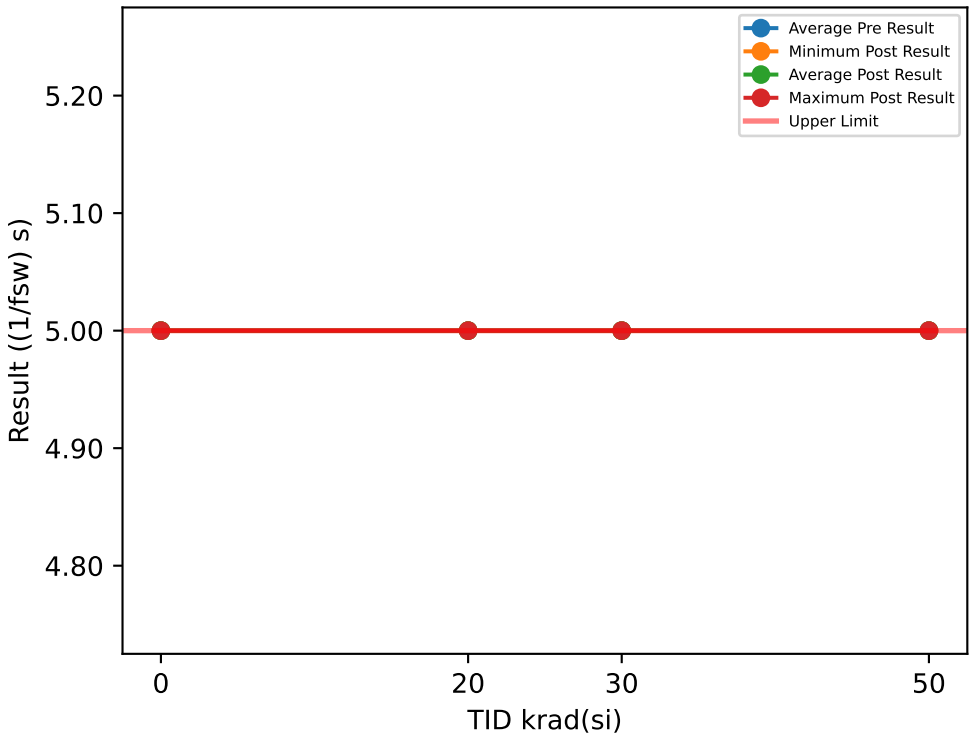
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	5	5	0
2	20	Unbiased	5	5	0
3	50	Biased	5	5	0
4	30	Unbiased	5	5	0
5	50	Unbiased	5	5	0
6	30	Biased	5	5	0
7	50	Biased	5	5	0
8	30	Unbiased	5	5	0
9	20	Unbiased	5	5	0
10	50	Biased	5	5	0
11	30	Biased	5	5	0
12	0	Correlation	5	5	0
13	0	Correlation	5	5	0
14	50	Unbiased	5	5	0
15	20	Biased	5	5	0
16	20	Unbiased	5	5	0
17	20	Biased	5	5	0
18	20	Unbiased	5	5	0
19	20	Biased	5	5	0
20	50	Unbiased	5	5	0
21	0	Correlation	5	5	0
22	50	Unbiased	5	5	0
23	0	Correlation	5	5	0
24	20	Biased	5	5	0
26	50	Biased	5	5	0
27	30	Unbiased	5	5	0
28	30	Biased	5	5	0
29	30	Unbiased	5	5	0
30	20	Biased	5	5	0
31	30	Unbiased	5	5	0
33	30	Biased	5	5	0
34	50	Unbiased	5	5	0
35	20	Unbiased	5	5	0
41	30	Biased	5	5	0

Test Statistics ((1/fsw) s)

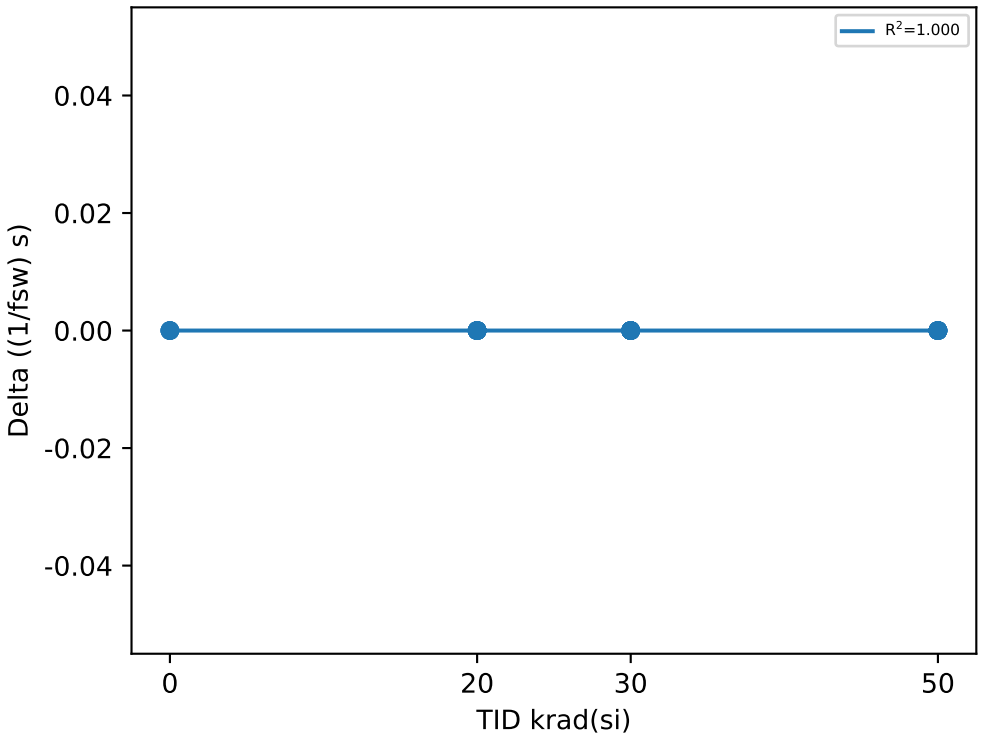
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5	5	5	0	5	5	5	0	0	0	0	0
20	5	5	5	0	5	5	5	0	0	0	0	0
30	5	5	5	0	5	5	5	0	0	0	0	0
50	5	5	5	0	5	5	5	0	0	0	0	0

Device Test: 20.120 FREQ|DETECTION/SYNC/4.5/4.5/0/0/4.5/200kHz//@T_SYNC_DET

TID vs Result Stats



TID vs Post - Pre Exposure Delta



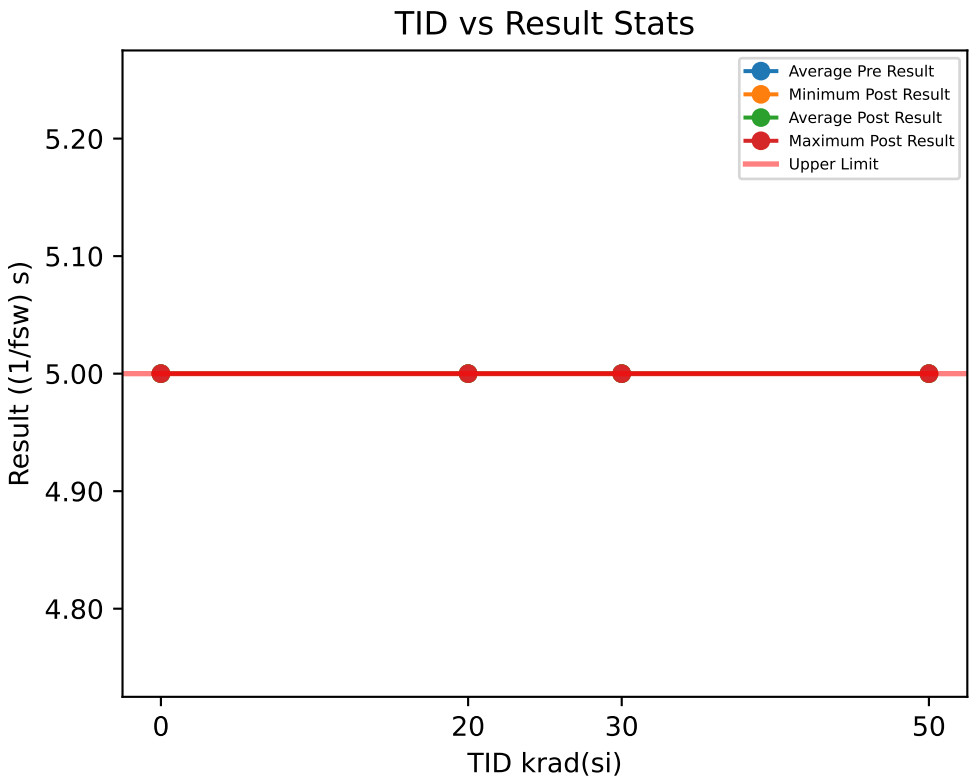
Test Results (Upper Limit = 5.0 ((1/fsw) s))

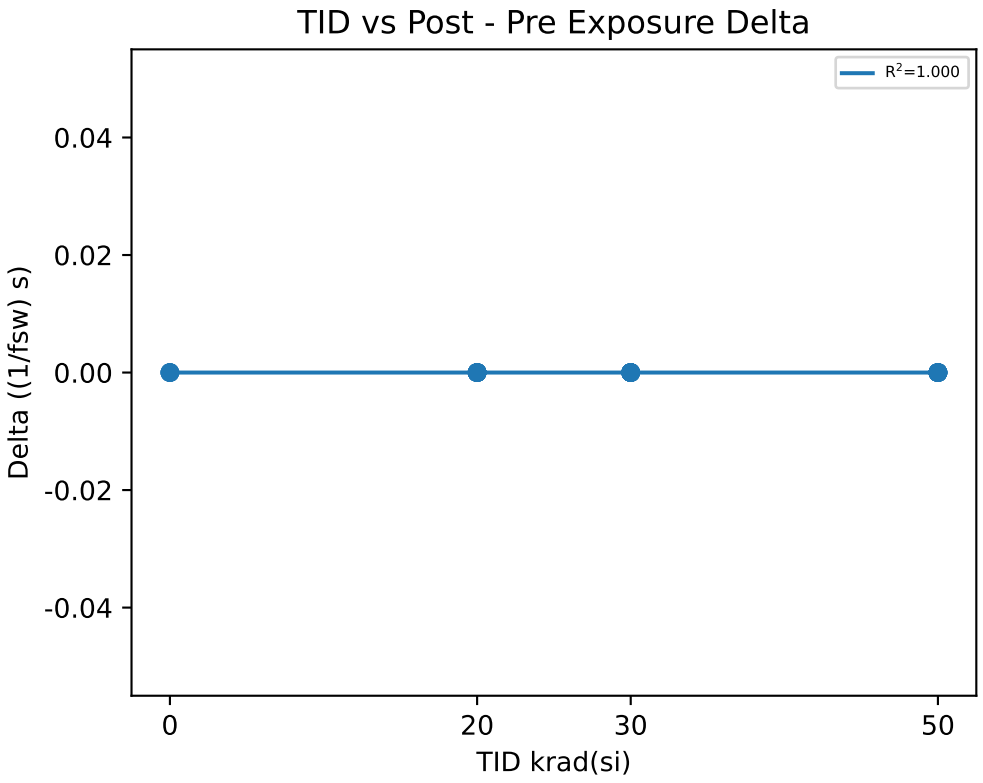
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	5	5	0
2	20	Unbiased	5	5	0
3	50	Biased	5	5	0
4	30	Unbiased	5	5	0
5	50	Unbiased	5	5	0
6	30	Biased	5	5	0
7	50	Biased	5	5	0
8	30	Unbiased	5	5	0
9	20	Unbiased	5	5	0
10	50	Biased	5	5	0
11	30	Biased	5	5	0
12	0	Correlation	5	5	0
13	0	Correlation	5	5	0
14	50	Unbiased	5	5	0
15	20	Biased	5	5	0
16	20	Unbiased	5	5	0
17	20	Biased	5	5	0
18	20	Unbiased	5	5	0
19	20	Biased	5	5	0
20	50	Unbiased	5	5	0
21	0	Correlation	5	5	0
22	50	Unbiased	5	5	0
23	0	Correlation	5	5	0
24	20	Biased	5	5	0
26	50	Biased	5	5	0
27	30	Unbiased	5	5	0
28	30	Biased	5	5	0
29	30	Unbiased	5	5	0
30	20	Biased	5	5	0
31	30	Unbiased	5	5	0
33	30	Biased	5	5	0
34	50	Unbiased	5	5	0
35	20	Unbiased	5	5	0
41	30	Biased	5	5	0

Test Statistics ((1/fsw) s)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5	5	5	0	5	5	5	0	0	0	0	0
20	5	5	5	0	5	5	5	0	0	0	0	0
30	5	5	5	0	5	5	5	0	0	0	0	0
50	5	5	5	0	5	5	5	0	0	0	0	0

Device Test: 20.122 FREQ|DETECTION/SYNC/5/5/0/0/5/200kHz//@T_SYNC_DET





Test Results (Upper Limit = 5.0 ((1/fsw) s))

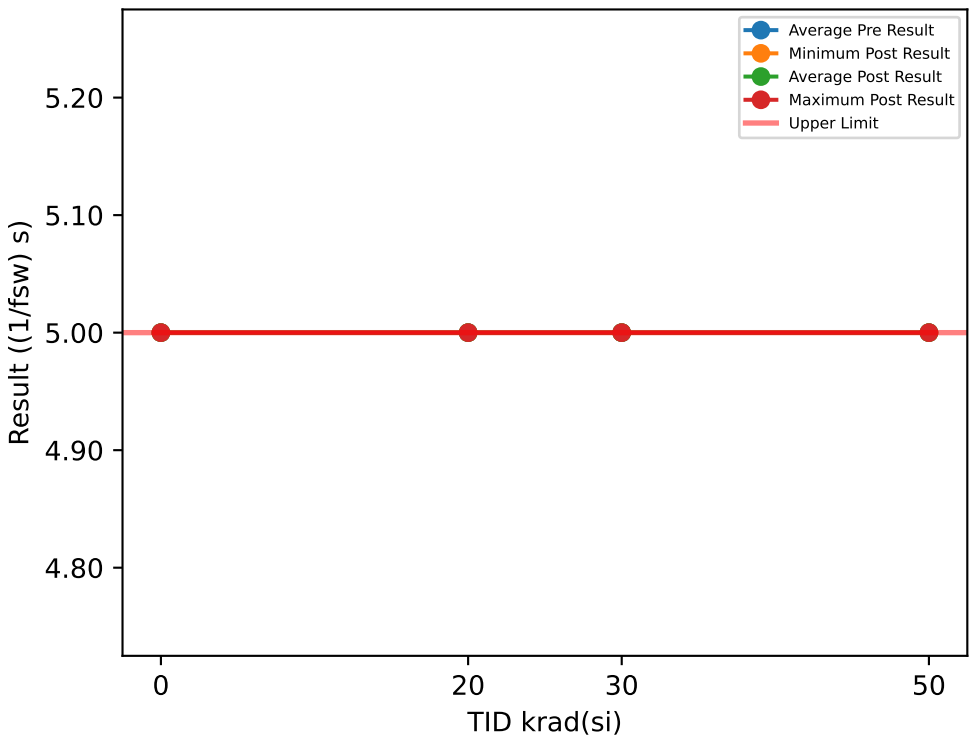
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	5	5	0
2	20	Unbiased	5	5	0
3	50	Biased	5	5	0
4	30	Unbiased	5	5	0
5	50	Unbiased	5	5	0
6	30	Biased	5	5	0
7	50	Biased	5	5	0
8	30	Unbiased	5	5	0
9	20	Unbiased	5	5	0
10	50	Biased	5	5	0
11	30	Biased	5	5	0
12	0	Correlation	5	5	0
13	0	Correlation	5	5	0
14	50	Unbiased	5	5	0
15	20	Biased	5	5	0
16	20	Unbiased	5	5	0
17	20	Biased	5	5	0
18	20	Unbiased	5	5	0
19	20	Biased	5	5	0
20	50	Unbiased	5	5	0
21	0	Correlation	5	5	0
22	50	Unbiased	5	5	0
23	0	Correlation	5	5	0
24	20	Biased	5	5	0
26	50	Biased	5	5	0
27	30	Unbiased	5	5	0
28	30	Biased	5	5	0
29	30	Unbiased	5	5	0
30	20	Biased	5	5	0
31	30	Unbiased	5	5	0
33	30	Biased	5	5	0
34	50	Unbiased	5	5	0
35	20	Unbiased	5	5	0
41	30	Biased	5	5	0

Test Statistics ((1/fsw) s)

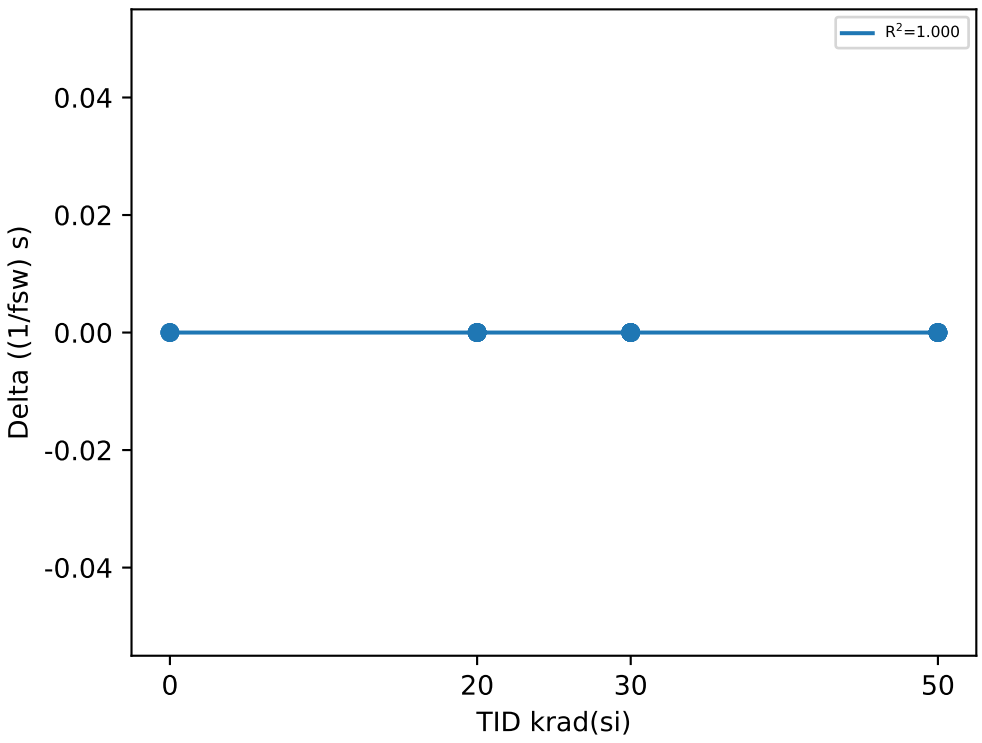
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5	5	5	0	5	5	5	0	0	0	0	0
20	5	5	5	0	5	5	5	0	0	0	0	0
30	5	5	5	0	5	5	5	0	0	0	0	0
50	5	5	5	0	5	5	5	0	0	0	0	0

Device Test: 20.124 FREQ|DETECTION/SYNC/12/12/0/0/5/200kHz//@T_SYNC_DET

TID vs Result Stats



TID vs Post - Pre Exposure Delta



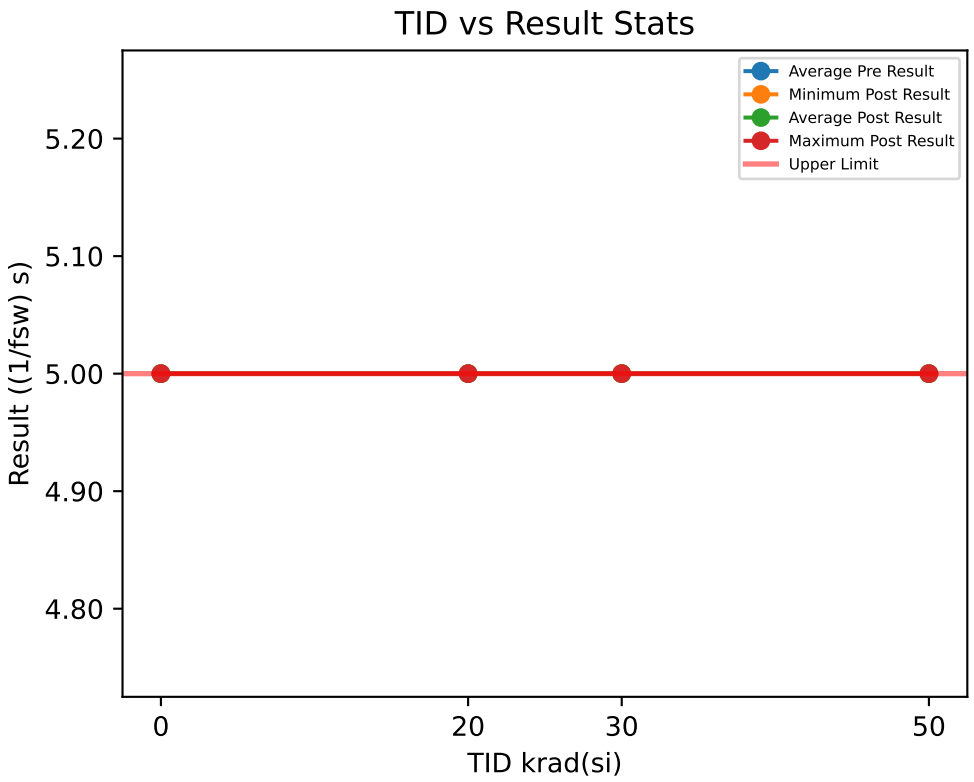
Test Results (Upper Limit = 5.0 ((1/fsw) s))

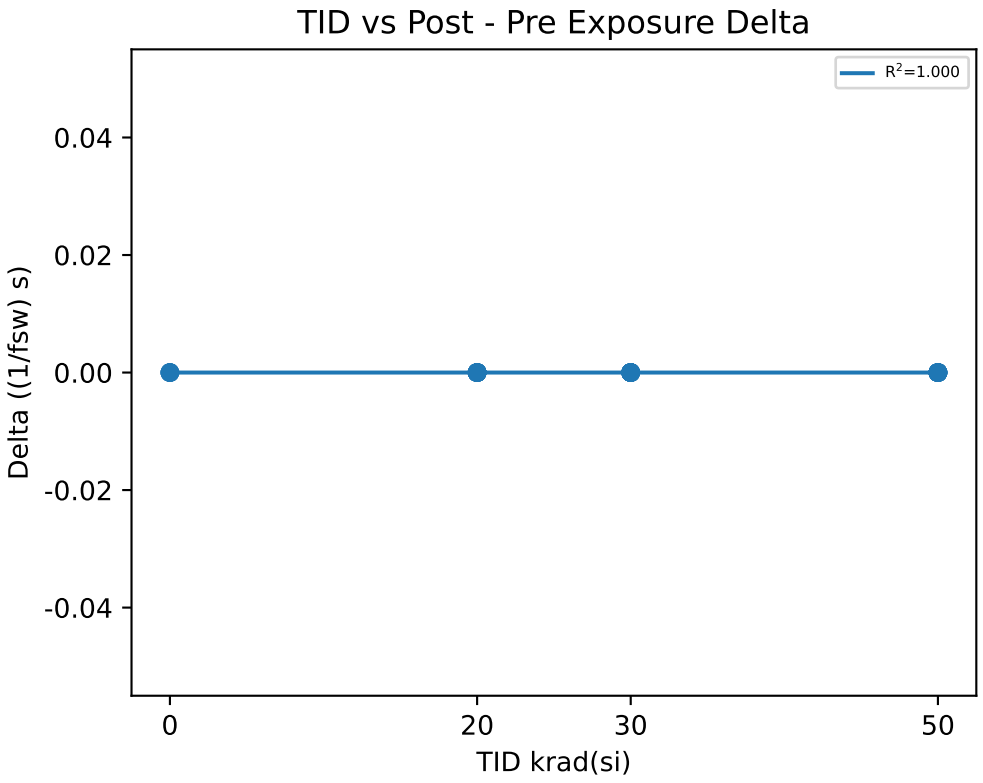
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	5	5	0
2	20	Unbiased	5	5	0
3	50	Biased	5	5	0
4	30	Unbiased	5	5	0
5	50	Unbiased	5	5	0
6	30	Biased	5	5	0
7	50	Biased	5	5	0
8	30	Unbiased	5	5	0
9	20	Unbiased	5	5	0
10	50	Biased	5	5	0
11	30	Biased	5	5	0
12	0	Correlation	5	5	0
13	0	Correlation	5	5	0
14	50	Unbiased	5	5	0
15	20	Biased	5	5	0
16	20	Unbiased	5	5	0
17	20	Biased	5	5	0
18	20	Unbiased	5	5	0
19	20	Biased	5	5	0
20	50	Unbiased	5	5	0
21	0	Correlation	5	5	0
22	50	Unbiased	5	5	0
23	0	Correlation	5	5	0
24	20	Biased	5	5	0
26	50	Biased	5	5	0
27	30	Unbiased	5	5	0
28	30	Biased	5	5	0
29	30	Unbiased	5	5	0
30	20	Biased	5	5	0
31	30	Unbiased	5	5	0
33	30	Biased	5	5	0
34	50	Unbiased	5	5	0
35	20	Unbiased	5	5	0
41	30	Biased	5	5	0

Test Statistics ((1/fsw) s)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5	5	5	0	5	5	5	0	0	0	0	0
20	5	5	5	0	5	5	5	0	0	0	0	0
30	5	5	5	0	5	5	5	0	0	0	0	0
50	5	5	5	0	5	5	5	0	0	0	0	0

Device Test: 20.126 FREQ|DETECTION/SYNC/14/14/0/0/5/200kHz//@T_SYNC_DET





Test Results (Upper Limit = 5.0 ((1/fsw) s))

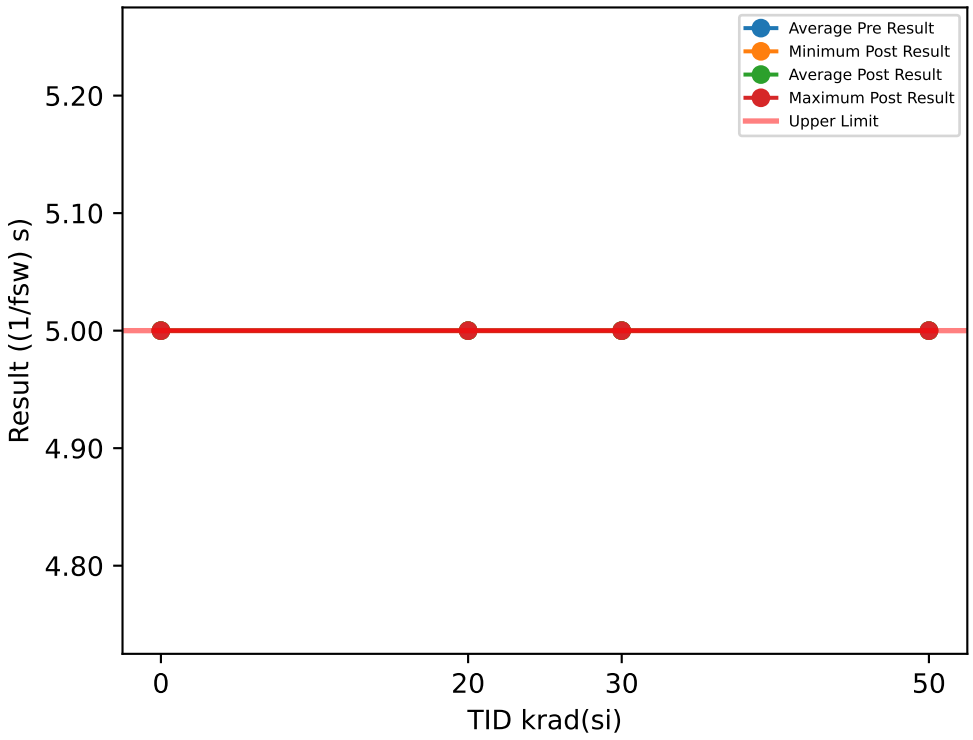
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	5	5	0
2	20	Unbiased	5	5	0
3	50	Biased	5	5	0
4	30	Unbiased	5	5	0
5	50	Unbiased	5	5	0
6	30	Biased	5	5	0
7	50	Biased	5	5	0
8	30	Unbiased	5	5	0
9	20	Unbiased	5	5	0
10	50	Biased	5	5	0
11	30	Biased	5	5	0
12	0	Correlation	5	5	0
13	0	Correlation	5	5	0
14	50	Unbiased	5	5	0
15	20	Biased	5	5	0
16	20	Unbiased	5	5	0
17	20	Biased	5	5	0
18	20	Unbiased	5	5	0
19	20	Biased	5	5	0
20	50	Unbiased	5	5	0
21	0	Correlation	5	5	0
22	50	Unbiased	5	5	0
23	0	Correlation	5	5	0
24	20	Biased	5	5	0
26	50	Biased	5	5	0
27	30	Unbiased	5	5	0
28	30	Biased	5	5	0
29	30	Unbiased	5	5	0
30	20	Biased	5	5	0
31	30	Unbiased	5	5	0
33	30	Biased	5	5	0
34	50	Unbiased	5	5	0
35	20	Unbiased	5	5	0
41	30	Biased	5	5	0

Test Statistics ((1/fsw) s)

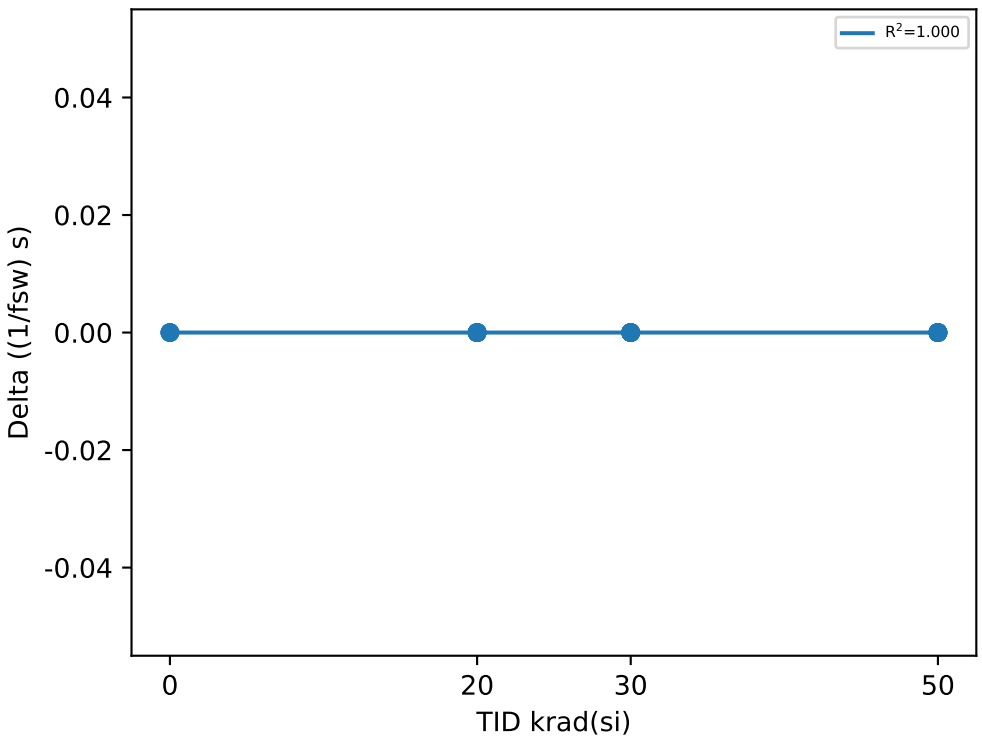
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5	5	5	0	5	5	5	0	0	0	0	0
20	5	5	5	0	5	5	5	0	0	0	0	0
30	5	5	5	0	5	5	5	0	0	0	0	0
50	5	5	5	0	5	5	5	0	0	0	0	0

Device Test: 20.128 FREQ|DETECTION/SYNC/4.5/4.5/0/0/4.5/500kHz//@T_SYNC_DET

TID vs Result Stats



TID vs Post - Pre Exposure Delta



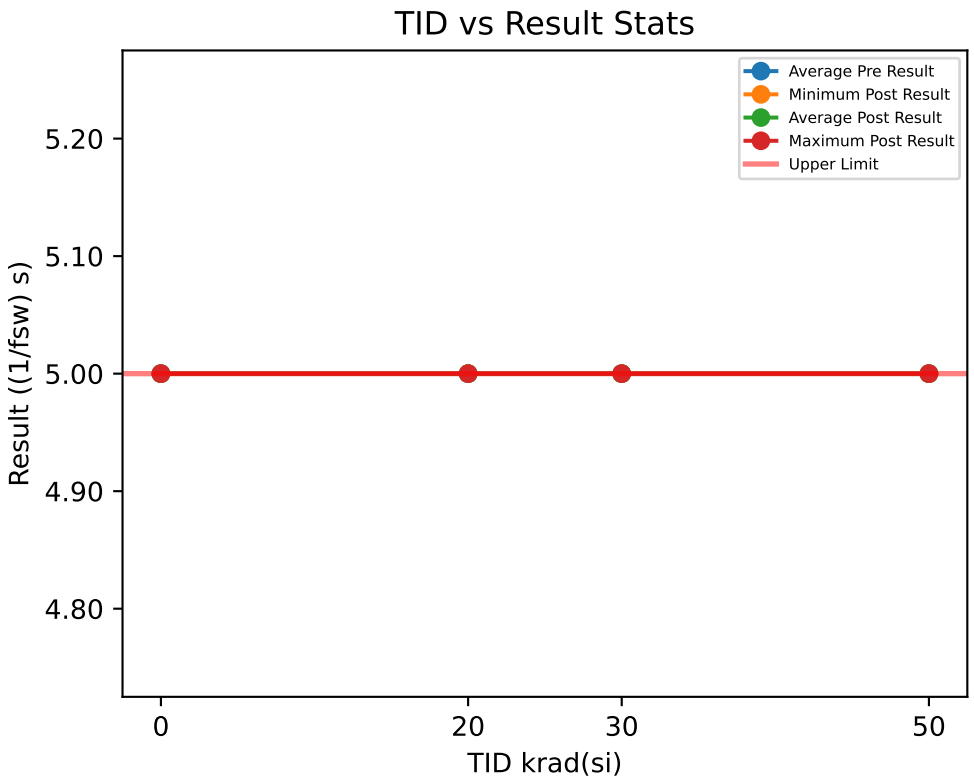
Test Results (Upper Limit = 5.0 ((1/fsw) s))

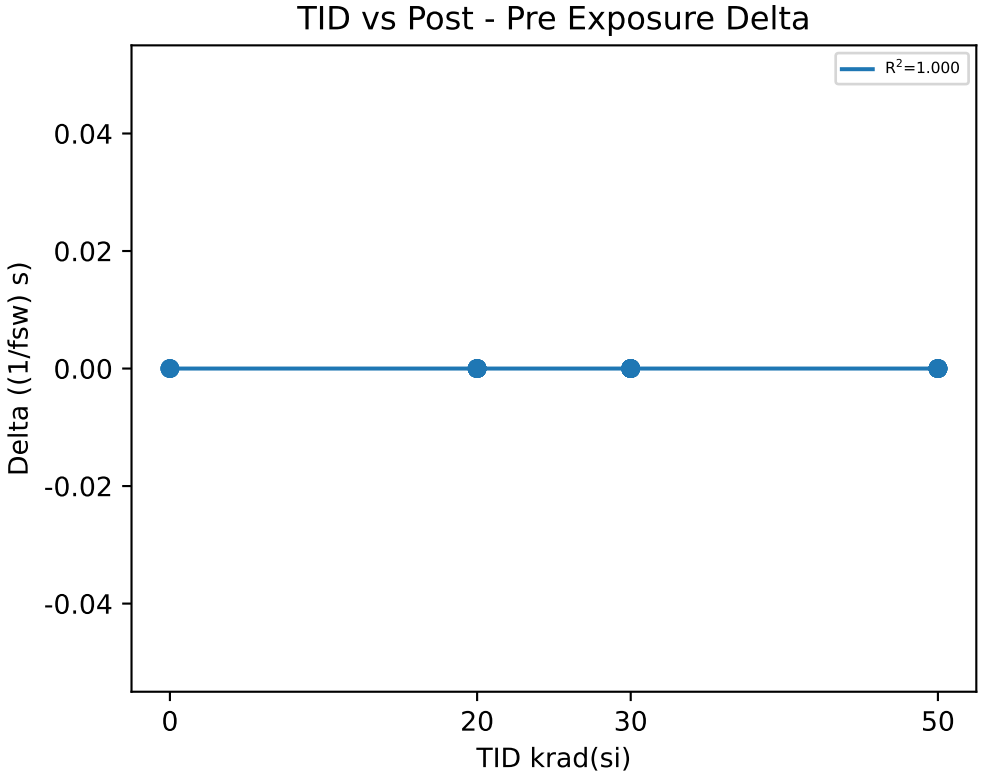
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	5	5	0
2	20	Unbiased	5	5	0
3	50	Biased	5	5	0
4	30	Unbiased	5	5	0
5	50	Unbiased	5	5	0
6	30	Biased	5	5	0
7	50	Biased	5	5	0
8	30	Unbiased	5	5	0
9	20	Unbiased	5	5	0
10	50	Biased	5	5	0
11	30	Biased	5	5	0
12	0	Correlation	5	5	0
13	0	Correlation	5	5	0
14	50	Unbiased	5	5	0
15	20	Biased	5	5	0
16	20	Unbiased	5	5	0
17	20	Biased	5	5	0
18	20	Unbiased	5	5	0
19	20	Biased	5	5	0
20	50	Unbiased	5	5	0
21	0	Correlation	5	5	0
22	50	Unbiased	5	5	0
23	0	Correlation	5	5	0
24	20	Biased	5	5	0
26	50	Biased	5	5	0
27	30	Unbiased	5	5	0
28	30	Biased	5	5	0
29	30	Unbiased	5	5	0
30	20	Biased	5	5	0
31	30	Unbiased	5	5	0
33	30	Biased	5	5	0
34	50	Unbiased	5	5	0
35	20	Unbiased	5	5	0
41	30	Biased	5	5	0

Test Statistics ((1/fsw) s)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5	5	5	0	5	5	5	0	0	0	0	0
20	5	5	5	0	5	5	5	0	0	0	0	0
30	5	5	5	0	5	5	5	0	0	0	0	0
50	5	5	5	0	5	5	5	0	0	0	0	0

Device Test: 20.130 FREQ|DETECTION/SYNC/5/5/0/0/5/500kHz//@T_SYNC_DET





Test Results (Upper Limit = 5.0 ((1/fsw) s))

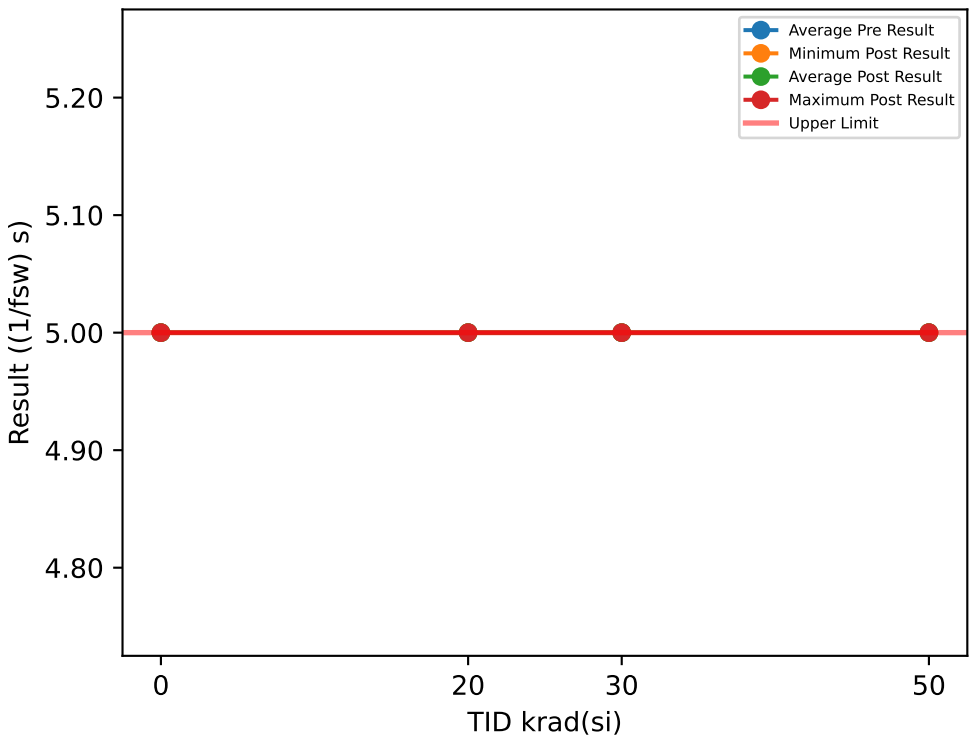
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	5	5	0
2	20	Unbiased	5	5	0
3	50	Biased	5	5	0
4	30	Unbiased	5	5	0
5	50	Unbiased	5	5	0
6	30	Biased	5	5	0
7	50	Biased	5	5	0
8	30	Unbiased	5	5	0
9	20	Unbiased	5	5	0
10	50	Biased	5	5	0
11	30	Biased	5	5	0
12	0	Correlation	5	5	0
13	0	Correlation	5	5	0
14	50	Unbiased	5	5	0
15	20	Biased	5	5	0
16	20	Unbiased	5	5	0
17	20	Biased	5	5	0
18	20	Unbiased	5	5	0
19	20	Biased	5	5	0
20	50	Unbiased	5	5	0
21	0	Correlation	5	5	0
22	50	Unbiased	5	5	0
23	0	Correlation	5	5	0
24	20	Biased	5	5	0
26	50	Biased	5	5	0
27	30	Unbiased	5	5	0
28	30	Biased	5	5	0
29	30	Unbiased	5	5	0
30	20	Biased	5	5	0
31	30	Unbiased	5	5	0
33	30	Biased	5	5	0
34	50	Unbiased	5	5	0
35	20	Unbiased	5	5	0
41	30	Biased	5	5	0

Test Statistics ((1/fsw) s)

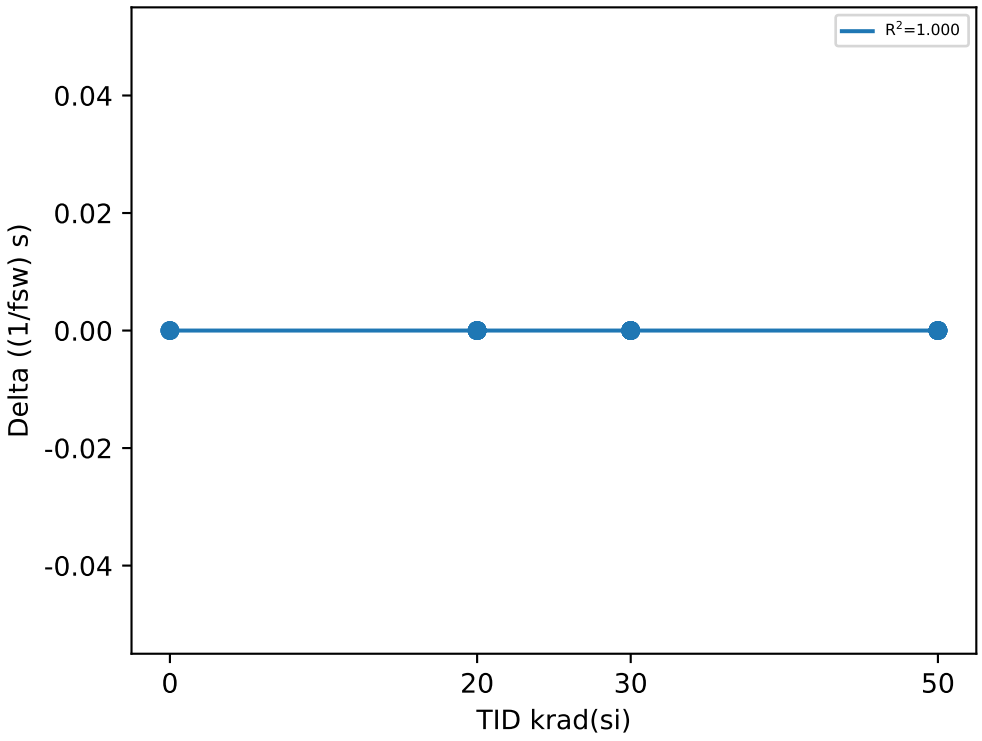
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5	5	5	0	5	5	5	0	0	0	0	0
20	5	5	5	0	5	5	5	0	0	0	0	0
30	5	5	5	0	5	5	5	0	0	0	0	0
50	5	5	5	0	5	5	5	0	0	0	0	0

Device Test: 20.132 FREQ|DETECTION/SYNC/12/12/0/0/5/500kHz//@T_SYNC_DET

TID vs Result Stats



TID vs Post - Pre Exposure Delta



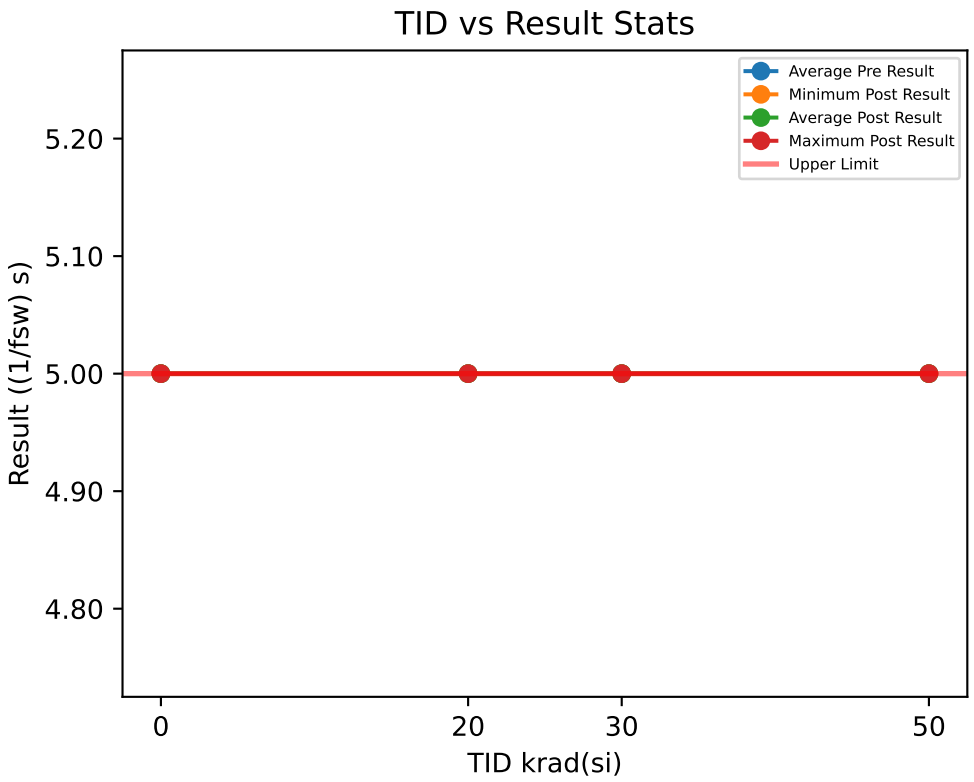
Test Results (Upper Limit = 5.0 ((1/fsw) s))

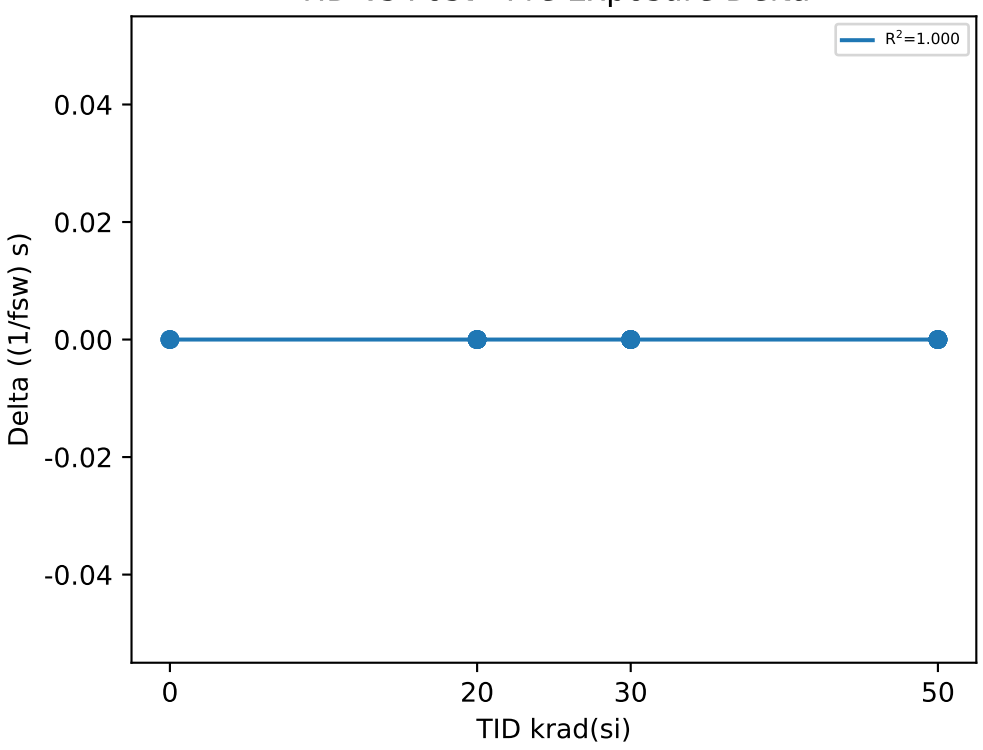
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	5	5	0
2	20	Unbiased	5	5	0
3	50	Biased	5	5	0
4	30	Unbiased	5	5	0
5	50	Unbiased	5	5	0
6	30	Biased	5	5	0
7	50	Biased	5	5	0
8	30	Unbiased	5	5	0
9	20	Unbiased	5	5	0
10	50	Biased	5	5	0
11	30	Biased	5	5	0
12	0	Correlation	5	5	0
13	0	Correlation	5	5	0
14	50	Unbiased	5	5	0
15	20	Biased	5	5	0
16	20	Unbiased	5	5	0
17	20	Biased	5	5	0
18	20	Unbiased	5	5	0
19	20	Biased	5	5	0
20	50	Unbiased	5	5	0
21	0	Correlation	5	5	0
22	50	Unbiased	5	5	0
23	0	Correlation	5	5	0
24	20	Biased	5	5	0
26	50	Biased	5	5	0
27	30	Unbiased	5	5	0
28	30	Biased	5	5	0
29	30	Unbiased	5	5	0
30	20	Biased	5	5	0
31	30	Unbiased	5	5	0
33	30	Biased	5	5	0
34	50	Unbiased	5	5	0
35	20	Unbiased	5	5	0
41	30	Biased	5	5	0

Test Statistics ((1/fsw) s)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5	5	5	0	5	5	5	0	0	0	0	0
20	5	5	5	0	5	5	5	0	0	0	0	0
30	5	5	5	0	5	5	5	0	0	0	0	0
50	5	5	5	0	5	5	5	0	0	0	0	0

Device Test: 20.134 FREQ|DETECTION/SYNC/14/14/0/0/5/500kHz//@T_SYNC_DET





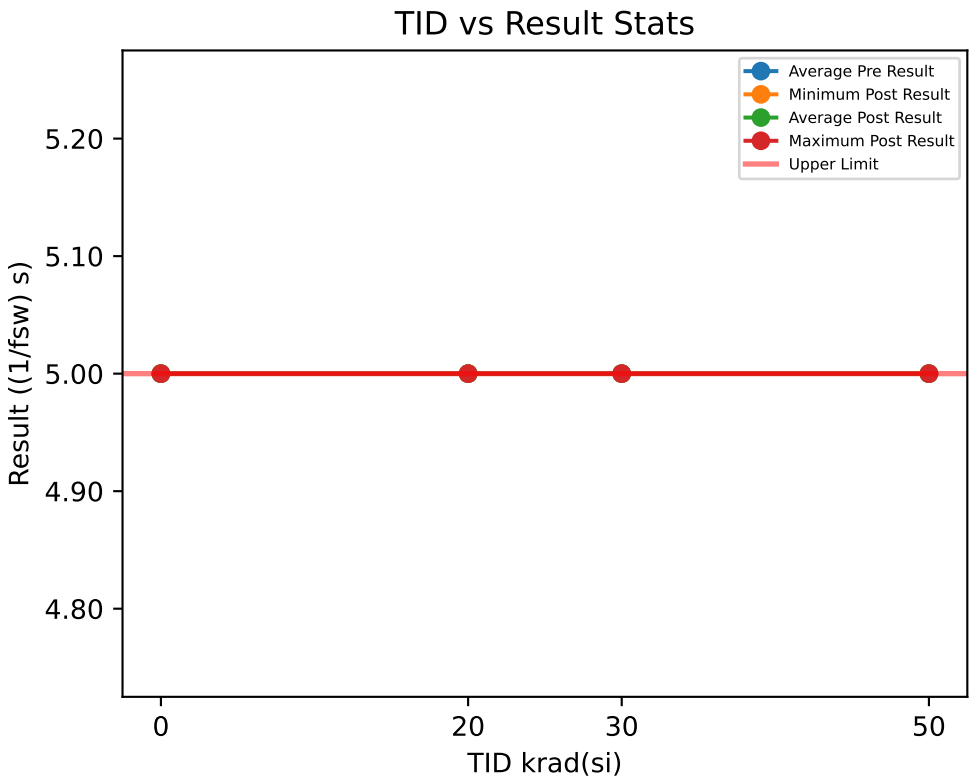
Test Results (Upper Limit = 5.0 ((1/fsw) s))

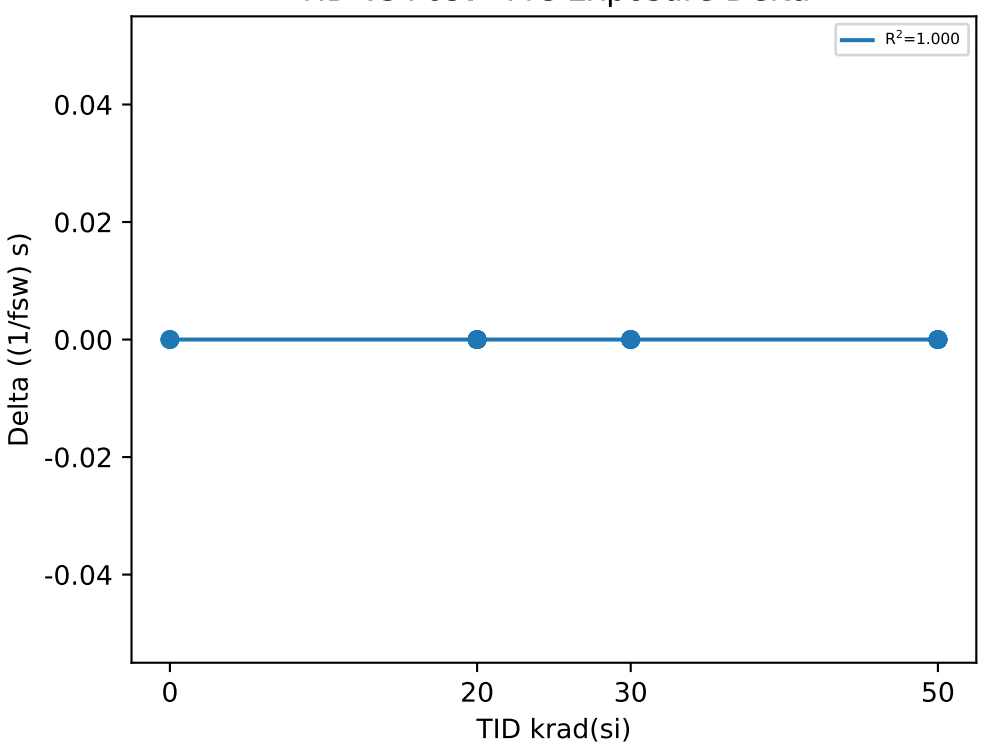
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	5	5	0
2	20	Unbiased	5	5	0
3	50	Biased	5	5	0
4	30	Unbiased	5	5	0
5	50	Unbiased	5	5	0
6	30	Biased	5	5	0
7	50	Biased	5	5	0
8	30	Unbiased	5	5	0
9	20	Unbiased	5	5	0
10	50	Biased	5	5	0
11	30	Biased	5	5	0
12	0	Correlation	5	5	0
13	0	Correlation	5	5	0
14	50	Unbiased	5	5	0
15	20	Biased	5	5	0
16	20	Unbiased	5	5	0
17	20	Biased	5	5	0
18	20	Unbiased	5	5	0
19	20	Biased	5	5	0
20	50	Unbiased	5	5	0
21	0	Correlation	5	5	0
22	50	Unbiased	5	5	0
23	0	Correlation	5	5	0
24	20	Biased	5	5	0
26	50	Biased	5	5	0
27	30	Unbiased	5	5	0
28	30	Biased	5	5	0
29	30	Unbiased	5	5	0
30	20	Biased	5	5	0
31	30	Unbiased	5	5	0
33	30	Biased	5	5	0
34	50	Unbiased	5	5	0
35	20	Unbiased	5	5	0
41	30	Biased	5	5	0

Test Statistics ((1/fsw) s)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5	5	5	0	5	5	5	0	0	0	0	0
20	5	5	5	0	5	5	5	0	0	0	0	0
30	5	5	5	0	5	5	5	0	0	0	0	0
50	5	5	5	0	5	5	5	0	0	0	0	0

Device Test: 20.136 FREQ|DETECTION/SYNC/4.5/4.5/0/0/4.5/1MHz//@T_SYNC_DET





Test Results (Upper Limit = 5.0 ((1/fsw) s))

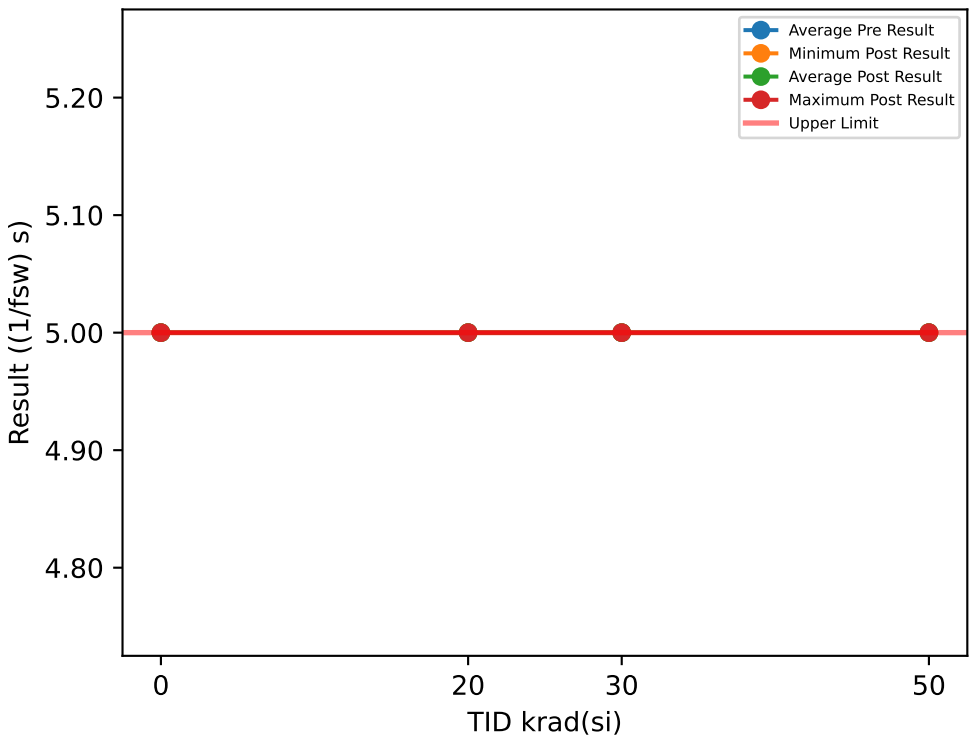
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	5	5	0
2	20	Unbiased	5	5	0
3	50	Biased	5	5	0
4	30	Unbiased	5	5	0
5	50	Unbiased	5	5	0
6	30	Biased	5	5	0
7	50	Biased	5	5	0
8	30	Unbiased	5	5	0
9	20	Unbiased	5	5	0
10	50	Biased	5	5	0
11	30	Biased	5	5	0
12	0	Correlation	5	5	0
13	0	Correlation	5	5	0
14	50	Unbiased	5	5	0
15	20	Biased	5	5	0
16	20	Unbiased	5	5	0
17	20	Biased	5	5	0
18	20	Unbiased	5	5	0
19	20	Biased	5	5	0
20	50	Unbiased	5	5	0
21	0	Correlation	5	5	0
22	50	Unbiased	5	5	0
23	0	Correlation	5	5	0
24	20	Biased	5	5	0
26	50	Biased	5	5	0
27	30	Unbiased	5	5	0
28	30	Biased	5	5	0
29	30	Unbiased	5	5	0
30	20	Biased	5	5	0
31	30	Unbiased	5	5	0
33	30	Biased	5	5	0
34	50	Unbiased	5	5	0
35	20	Unbiased	5	5	0
41	30	Biased	5	5	0

Test Statistics ((1/fsw) s)

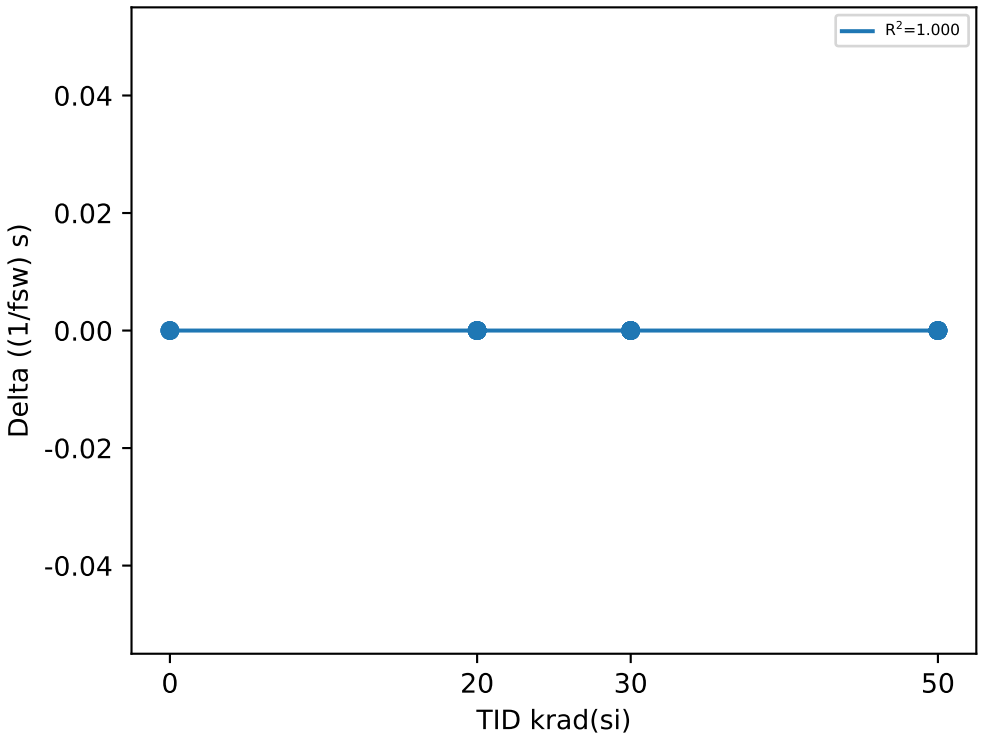
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5	5	5	0	5	5	5	0	0	0	0	0
20	5	5	5	0	5	5	5	0	0	0	0	0
30	5	5	5	0	5	5	5	0	0	0	0	0
50	5	5	5	0	5	5	5	0	0	0	0	0

Device Test: 20.138 FREQ|DETECTION/SYNC/5/5/0/0/5/1MHz//@T_SYNC_DET

TID vs Result Stats



TID vs Post - Pre Exposure Delta



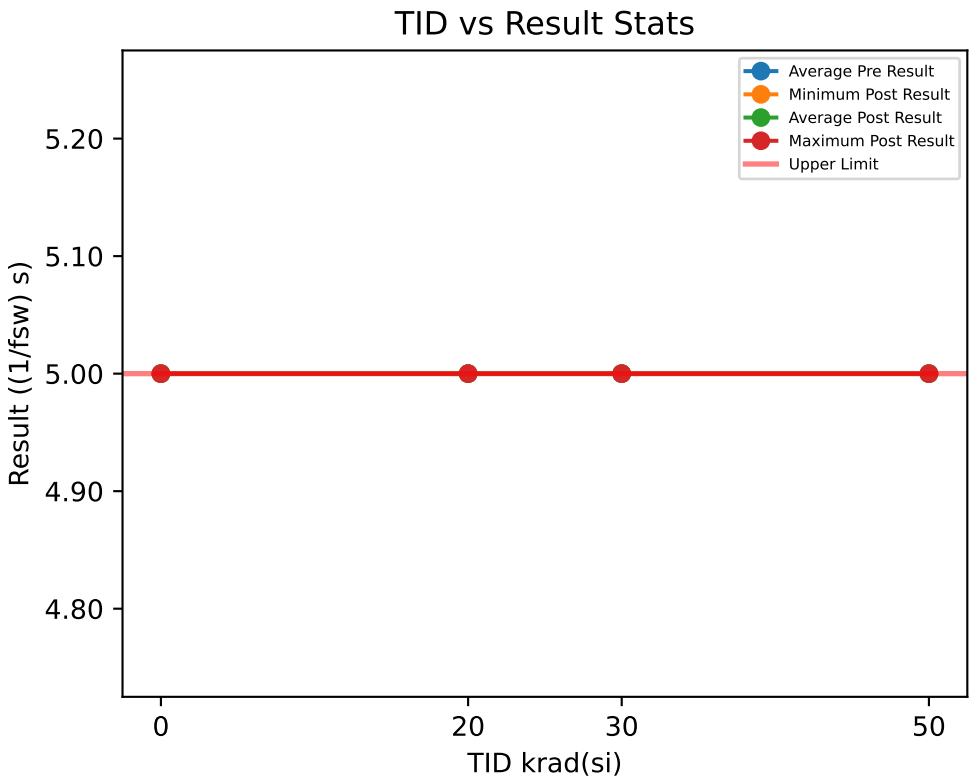
Test Results (Upper Limit = 5.0 ((1/fsw) s))

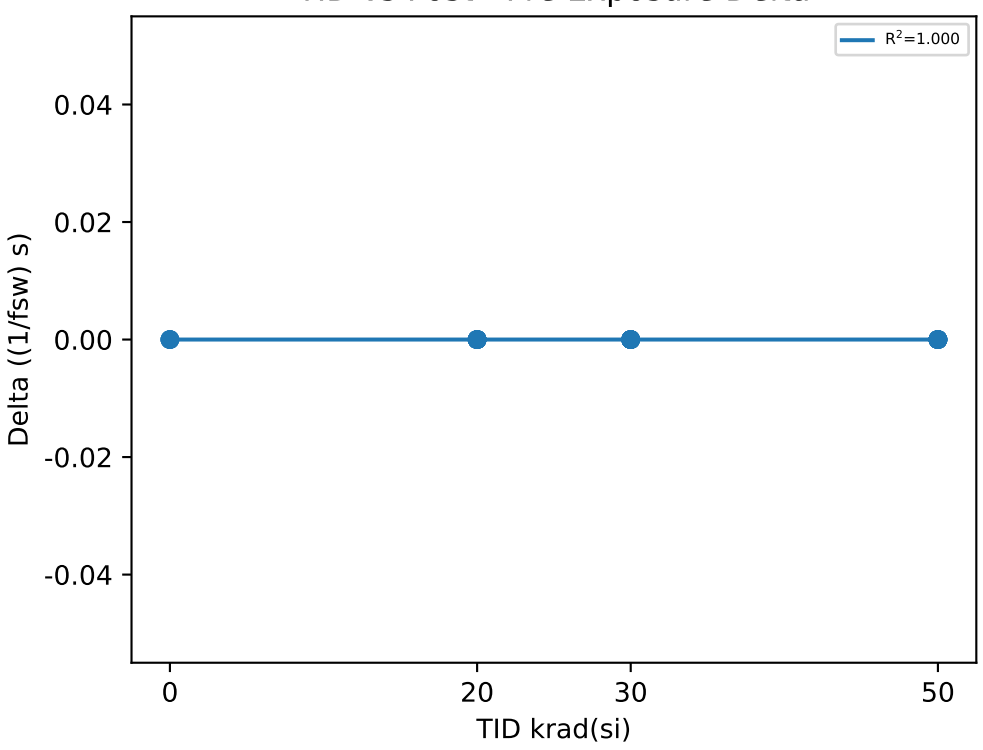
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	5	5	0
2	20	Unbiased	5	5	0
3	50	Biased	5	5	0
4	30	Unbiased	5	5	0
5	50	Unbiased	5	5	0
6	30	Biased	5	5	0
7	50	Biased	5	5	0
8	30	Unbiased	5	5	0
9	20	Unbiased	5	5	0
10	50	Biased	5	5	0
11	30	Biased	5	5	0
12	0	Correlation	5	5	0
13	0	Correlation	5	5	0
14	50	Unbiased	5	5	0
15	20	Biased	5	5	0
16	20	Unbiased	5	5	0
17	20	Biased	5	5	0
18	20	Unbiased	5	5	0
19	20	Biased	5	5	0
20	50	Unbiased	5	5	0
21	0	Correlation	5	5	0
22	50	Unbiased	5	5	0
23	0	Correlation	5	5	0
24	20	Biased	5	5	0
26	50	Biased	5	5	0
27	30	Unbiased	5	5	0
28	30	Biased	5	5	0
29	30	Unbiased	5	5	0
30	20	Biased	5	5	0
31	30	Unbiased	5	5	0
33	30	Biased	5	5	0
34	50	Unbiased	5	5	0
35	20	Unbiased	5	5	0
41	30	Biased	5	5	0

Test Statistics ((1/fsw) s)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5	5	5	0	5	5	5	0	0	0	0	0
20	5	5	5	0	5	5	5	0	0	0	0	0
30	5	5	5	0	5	5	5	0	0	0	0	0
50	5	5	5	0	5	5	5	0	0	0	0	0

Device Test: 20.140 FREQ|DETECTION/SYNC/12/12/0/0/5/1MHz//@T_SYNC_DET





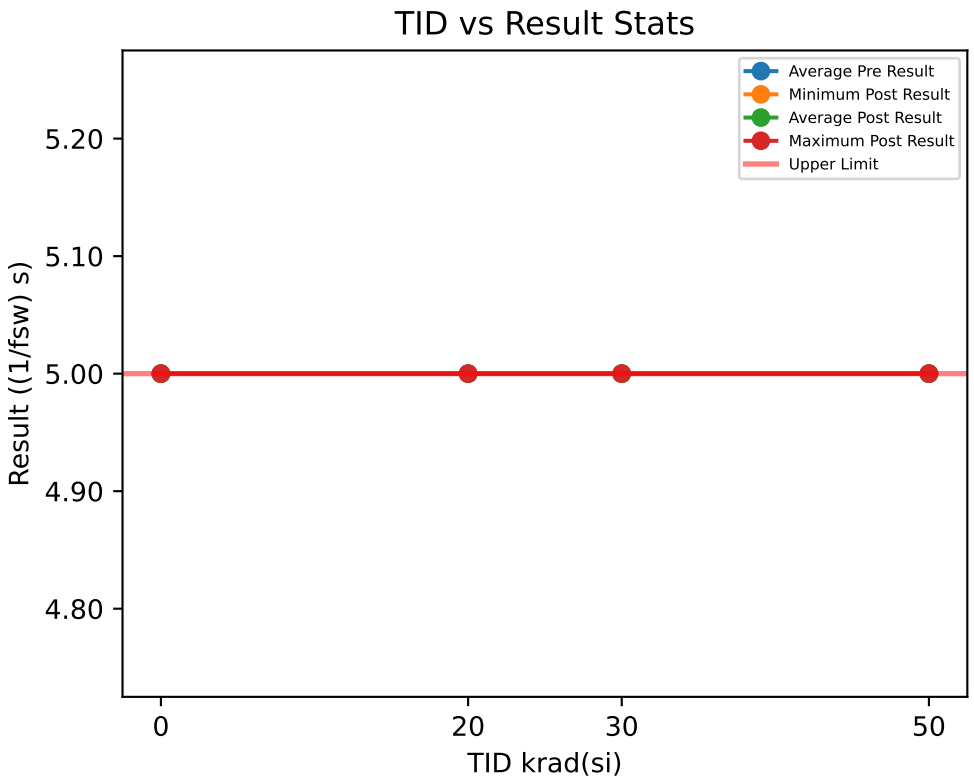
Test Results (Upper Limit = 5.0 ((1/fsw) s))

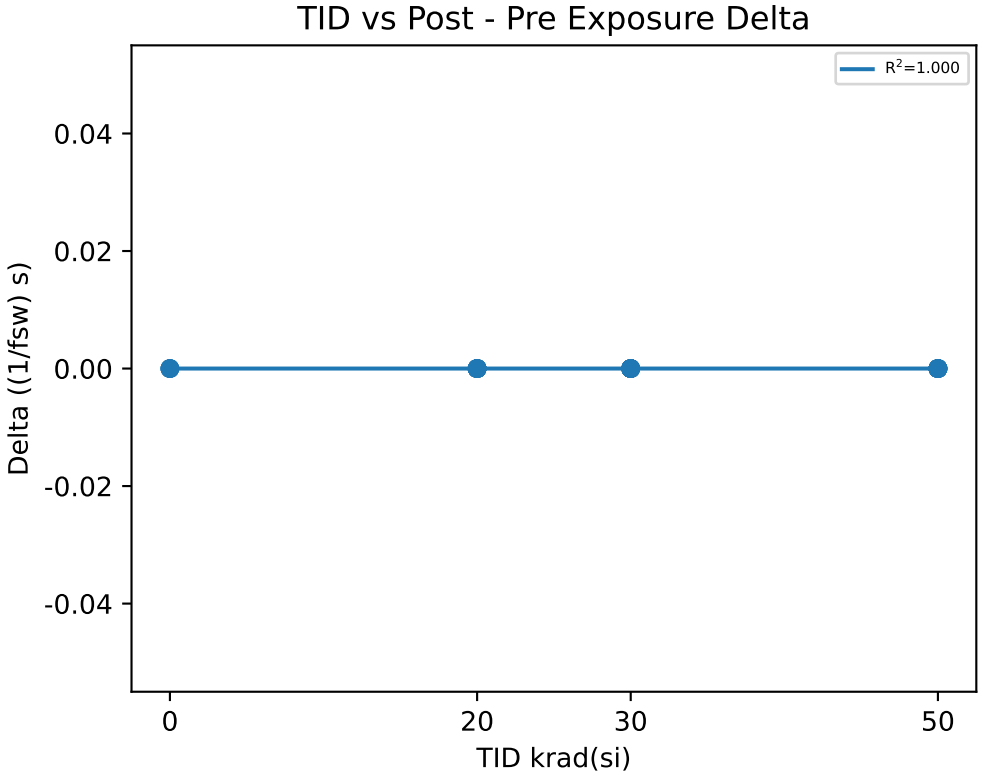
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	5	5	0
2	20	Unbiased	5	5	0
3	50	Biased	5	5	0
4	30	Unbiased	5	5	0
5	50	Unbiased	5	5	0
6	30	Biased	5	5	0
7	50	Biased	5	5	0
8	30	Unbiased	5	5	0
9	20	Unbiased	5	5	0
10	50	Biased	5	5	0
11	30	Biased	5	5	0
12	0	Correlation	5	5	0
13	0	Correlation	5	5	0
14	50	Unbiased	5	5	0
15	20	Biased	5	5	0
16	20	Unbiased	5	5	0
17	20	Biased	5	5	0
18	20	Unbiased	5	5	0
19	20	Biased	5	5	0
20	50	Unbiased	5	5	0
21	0	Correlation	5	5	0
22	50	Unbiased	5	5	0
23	0	Correlation	5	5	0
24	20	Biased	5	5	0
26	50	Biased	5	5	0
27	30	Unbiased	5	5	0
28	30	Biased	5	5	0
29	30	Unbiased	5	5	0
30	20	Biased	5	5	0
31	30	Unbiased	5	5	0
33	30	Biased	5	5	0
34	50	Unbiased	5	5	0
35	20	Unbiased	5	5	0
41	30	Biased	5	5	0

Test Statistics ((1/fsw) s)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5	5	5	0	5	5	5	0	0	0	0	0
20	5	5	5	0	5	5	5	0	0	0	0	0
30	5	5	5	0	5	5	5	0	0	0	0	0
50	5	5	5	0	5	5	5	0	0	0	0	0

Device Test: 20.142 FREQ|DETECTION/SYNC/14/14/0/0/5/1MHz//@T_SYNC_DET





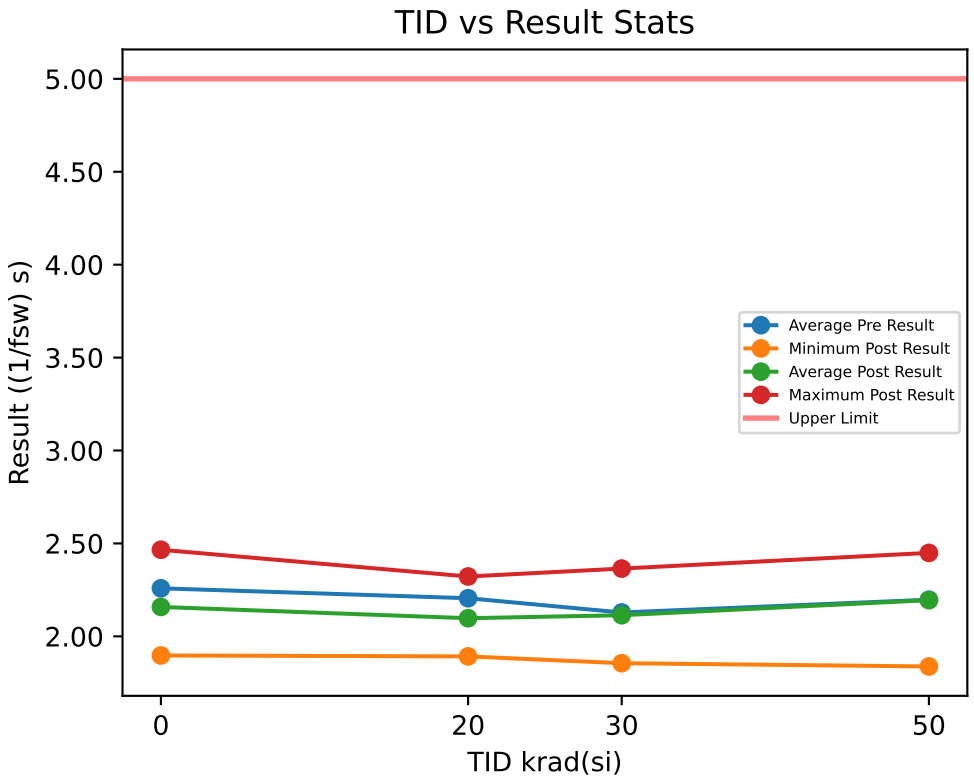
Test Results (Upper Limit = 5.0 ((1/fsw) s))

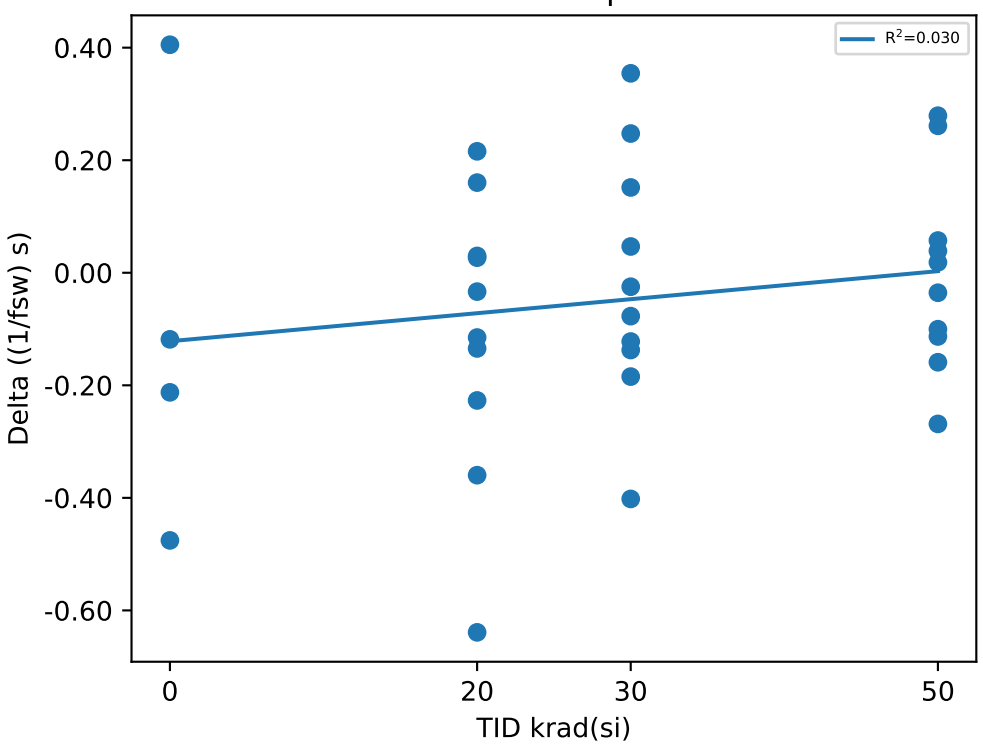
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	5	5	0
2	20	Unbiased	5	5	0
3	50	Biased	5	5	0
4	30	Unbiased	5	5	0
5	50	Unbiased	5	5	0
6	30	Biased	5	5	0
7	50	Biased	5	5	0
8	30	Unbiased	5	5	0
9	20	Unbiased	5	5	0
10	50	Biased	5	5	0
11	30	Biased	5	5	0
12	0	Correlation	5	5	0
13	0	Correlation	5	5	0
14	50	Unbiased	5	5	0
15	20	Biased	5	5	0
16	20	Unbiased	5	5	0
17	20	Biased	5	5	0
18	20	Unbiased	5	5	0
19	20	Biased	5	5	0
20	50	Unbiased	5	5	0
21	0	Correlation	5	5	0
22	50	Unbiased	5	5	0
23	0	Correlation	5	5	0
24	20	Biased	5	5	0
26	50	Biased	5	5	0
27	30	Unbiased	5	5	0
28	30	Biased	5	5	0
29	30	Unbiased	5	5	0
30	20	Biased	5	5	0
31	30	Unbiased	5	5	0
33	30	Biased	5	5	0
34	50	Unbiased	5	5	0
35	20	Unbiased	5	5	0
41	30	Biased	5	5	0

Test Statistics ((1/fsw) s)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5	5	5	0	5	5	5	0	0	0	0	0
20	5	5	5	0	5	5	5	0	0	0	0	0
30	5	5	5	0	5	5	5	0	0	0	0	0
50	5	5	5	0	5	5	5	0	0	0	0	0

Device Test: 20.144 FREQ|DETECTION/RT/4.5/4.5/0/0/4.5/100kHz//@T_INT_CLK_DET





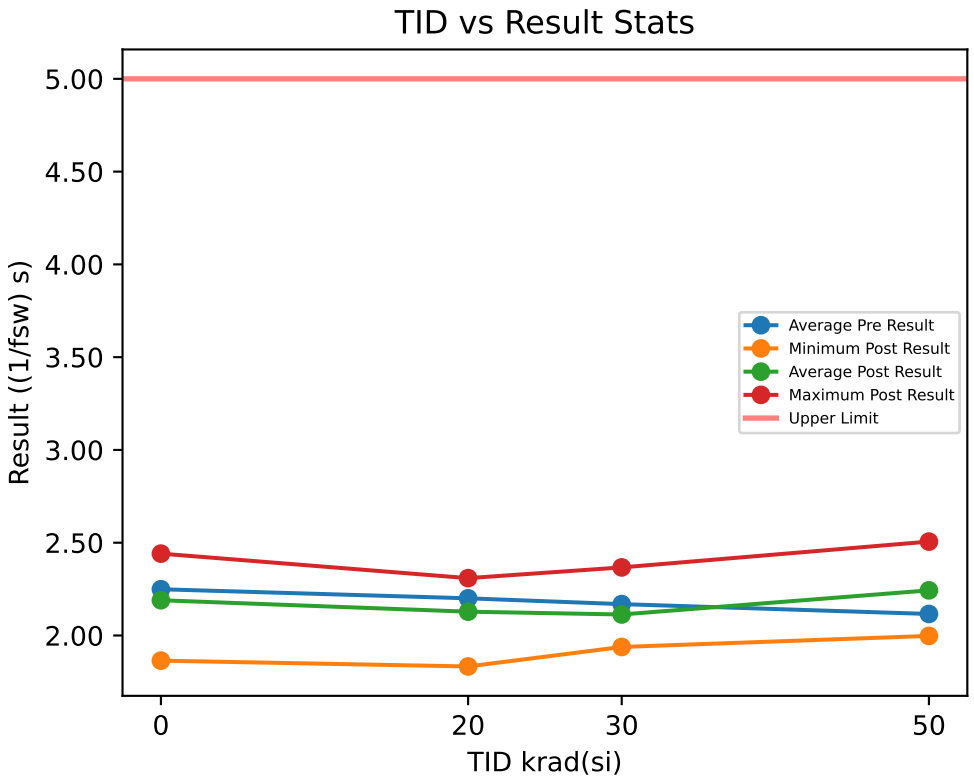
Test Results (Upper Limit = 5.0 ((1/fsw) s))

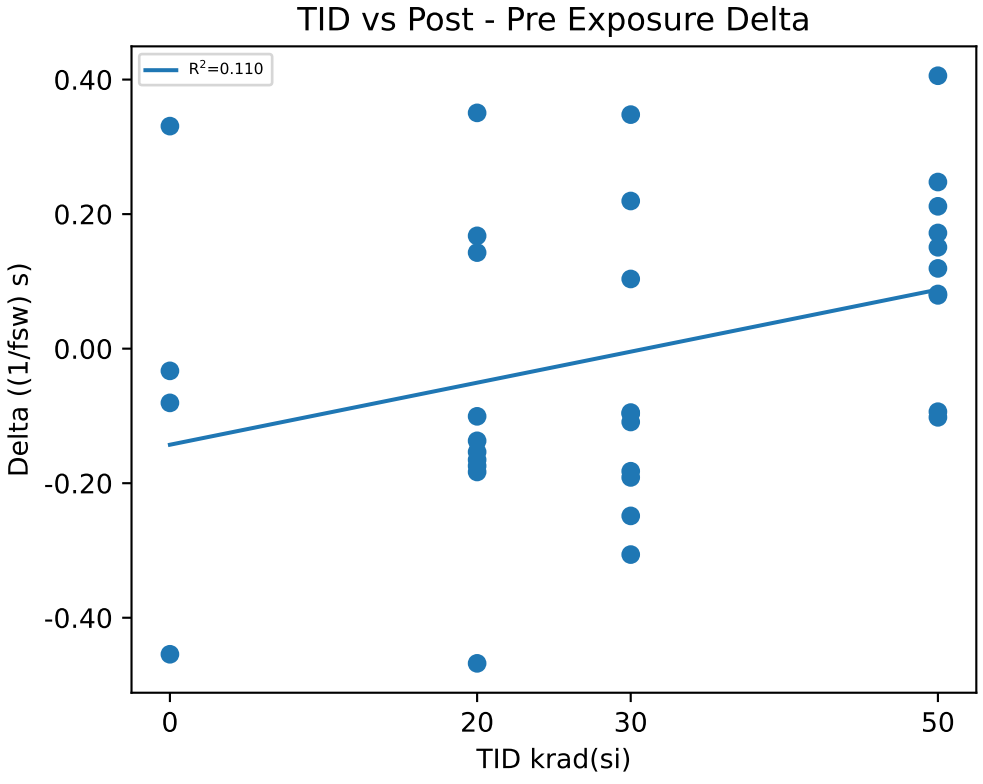
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	2.4242	2.3887	-0.0355
2	20	Unbiased	2.1063	2.3221	0.2158
3	50	Biased	2.253	2.2715	0.0185
4	30	Unbiased	2.0528	2.028	-0.0248
5	50	Unbiased	2.6208	2.3522	-0.2686
6	30	Biased	2.0103	2.3647	0.3544
7	50	Biased	2.1854	2.2242	0.0388
8	30	Unbiased	1.9928	1.8555	-0.1373
9	20	Unbiased	2.6097	1.9707	-0.639
10	50	Biased	2.17	2.4491	0.2791
11	30	Biased	2.1129	2.3603	0.2474
12	0	Correlation	2.0608	2.466	0.4052
13	0	Correlation	2.3196	2.2013	-0.1183
14	50	Unbiased	2.096	1.937	-0.159
15	20	Biased	2.4424	2.2155	-0.2269
16	20	Unbiased	2.1751	2.06	-0.1151
17	20	Biased	2.2518	1.8921	-0.3597
18	20	Unbiased	1.9642	1.9941	0.0299
19	20	Biased	2.3451	2.2106	-0.1345
20	50	Unbiased	1.9512	1.838	-0.1132
21	0	Correlation	2.281	2.0685	-0.2125
22	50	Unbiased	2.0611	2.1184	0.0573
23	0	Correlation	2.3727	1.8971	-0.4756
24	20	Biased	1.987	1.9535	-0.0335
26	50	Biased	2.0837	1.9834	-0.1003
27	30	Unbiased	2.1758	2.0987	-0.0771
28	30	Biased	1.9847	2.1363	0.1516
29	30	Unbiased	2.1504	2.1971	0.0467
30	20	Biased	2.0061	2.1663	0.1602
31	30	Unbiased	2.2702	1.8683	-0.4019
33	30	Biased	2.3166	2.1321	-0.1845
34	50	Unbiased	2.1246	2.3857	0.2611
35	20	Unbiased	2.1641	2.1909	0.0268
41	30	Biased	2.2178	2.0956	-0.1222

Test Statistics ((1/fsw) s)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.0608	2.2585	2.3727	0.13707	1.8971	2.1582	2.466	0.24001	-0.4756	-0.1003	0.4052	0.36937
20	1.9642	2.2052	2.6097	0.21064	1.8921	2.0976	2.3221	0.1421	-0.639	-0.1076	0.2158	0.2538
30	1.9847	2.1284	2.3166	0.11794	1.8555	2.1137	2.3647	0.17205	-0.4019	-0.01477	0.3544	0.22253
50	1.9512	2.197	2.6208	0.19505	1.838	2.1948	2.4491	0.21461	-0.2686	-0.00218	0.2791	0.17407

Device Test: 20.146 FREQ|DETECTION/RT/5/5/0/0/5/100kHz//@T_INT_CLK_DET





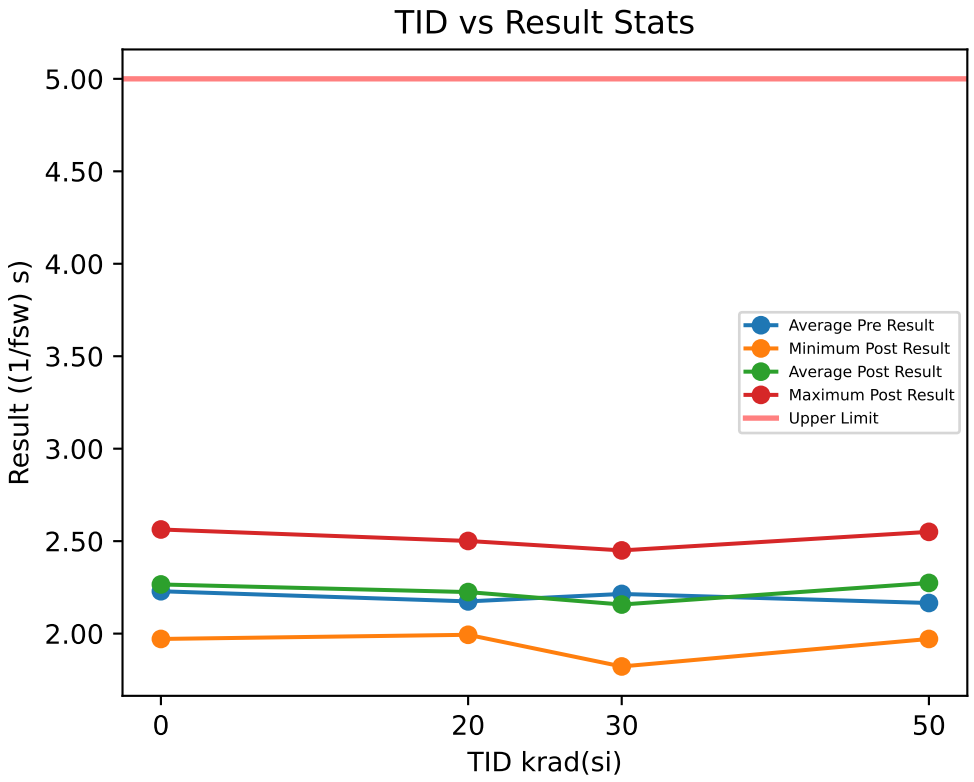
Test Results (Upper Limit = 5.0 ((1/fsw) s))

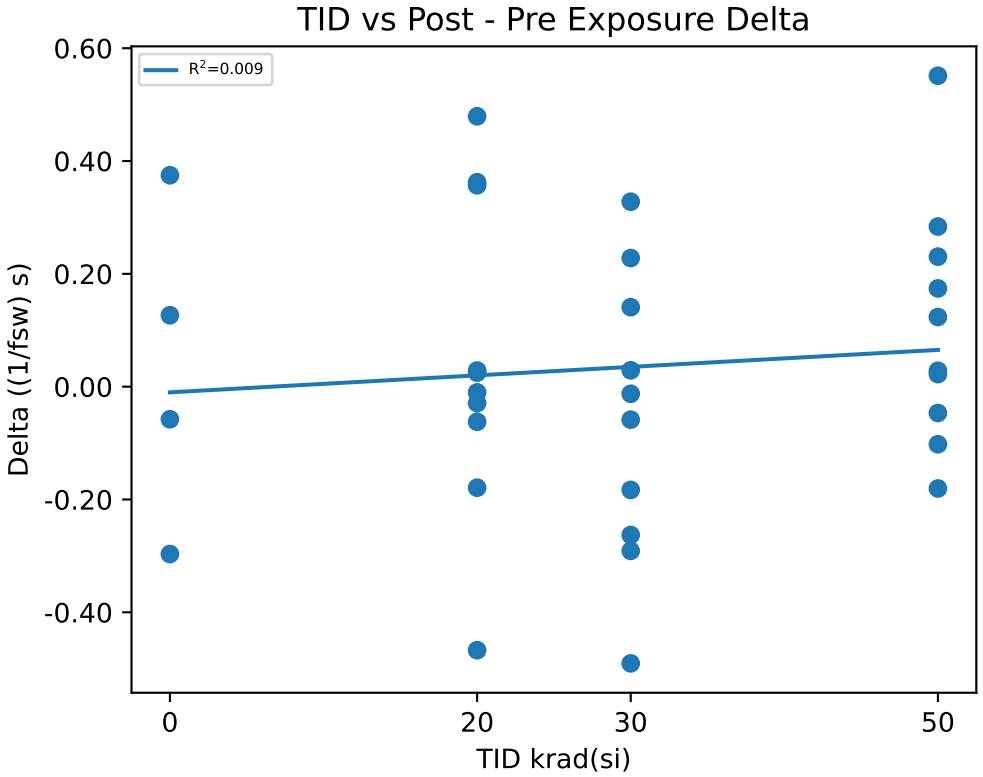
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	2.3441	2.242	-0.1021
2	20	Unbiased	1.8994	2.2499	0.3505
3	50	Biased	2.3553	2.506	0.1507
4	30	Unbiased	2.0529	1.9562	-0.0967
5	50	Unbiased	2.1541	2.4018	0.2477
6	30	Biased	2.1474	2.3669	0.2195
7	50	Biased	2.2475	2.3288	0.0813
8	30	Unbiased	1.9475	2.0511	0.1036
9	20	Unbiased	2.3247	2.1504	-0.1743
10	50	Biased	1.9286	2.3343	0.4057
11	30	Biased	2.329	2.1468	-0.1822
12	0	Correlation	2.1104	2.4412	0.3308
13	0	Correlation	2.2896	2.209	-0.0806
14	50	Unbiased	2.0913	1.9976	-0.0937
15	20	Biased	2.3941	2.2108	-0.1833
16	20	Unbiased	2.1814	2.0808	-0.1006
17	20	Biased	2.3545	1.8867	-0.4678
18	20	Unbiased	2.0114	2.1791	0.1677
19	20	Biased	2.3311	2.1941	-0.137
20	50	Unbiased	2.0536	2.2256	0.172
21	0	Correlation	2.2782	2.2452	-0.033
22	50	Unbiased	1.9311	2.0103	0.0792
23	0	Correlation	2.3187	1.8644	-0.4543
24	20	Biased	1.9866	1.8331	-0.1535
26	50	Biased	1.9208	2.0401	0.1193
27	30	Unbiased	2.3732	2.0671	-0.3061
28	30	Biased	1.7693	2.1172	0.3479
29	30	Unbiased	2.193	2.098	-0.095
30	20	Biased	2.1663	2.3091	0.1428
31	30	Unbiased	2.1867	1.9381	-0.2486
33	30	Biased	2.3491	2.2401	-0.109
34	50	Unbiased	2.1339	2.3455	0.2116
35	20	Unbiased	2.3541	2.1889	-0.1652
41	30	Biased	2.3421	2.1507	-0.1914

Test Statistics ((1/fsw) s)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.1104	2.2492	2.3187	0.094108	1.8644	2.19	2.4412	0.23981	-0.4543	-0.059275	0.3308	0.32112
20	1.8994	2.2004	2.3941	0.17981	1.8331	2.1283	2.3091	0.15388	-0.4678	-0.07207	0.3505	0.23142
30	1.7693	2.169	2.3732	0.19815	1.9381	2.1132	2.3669	0.12673	-0.3061	-0.0558	0.3479	0.21197
50	1.9208	2.116	2.3553	0.16339	1.9976	2.2432	2.506	0.17526	-0.1021	0.12717	0.4057	0.15188

Device Test: 20.148 FREQ|DETECTION/RT/12/12/0/0/5/100kHz//@T_INT_CLK_DET





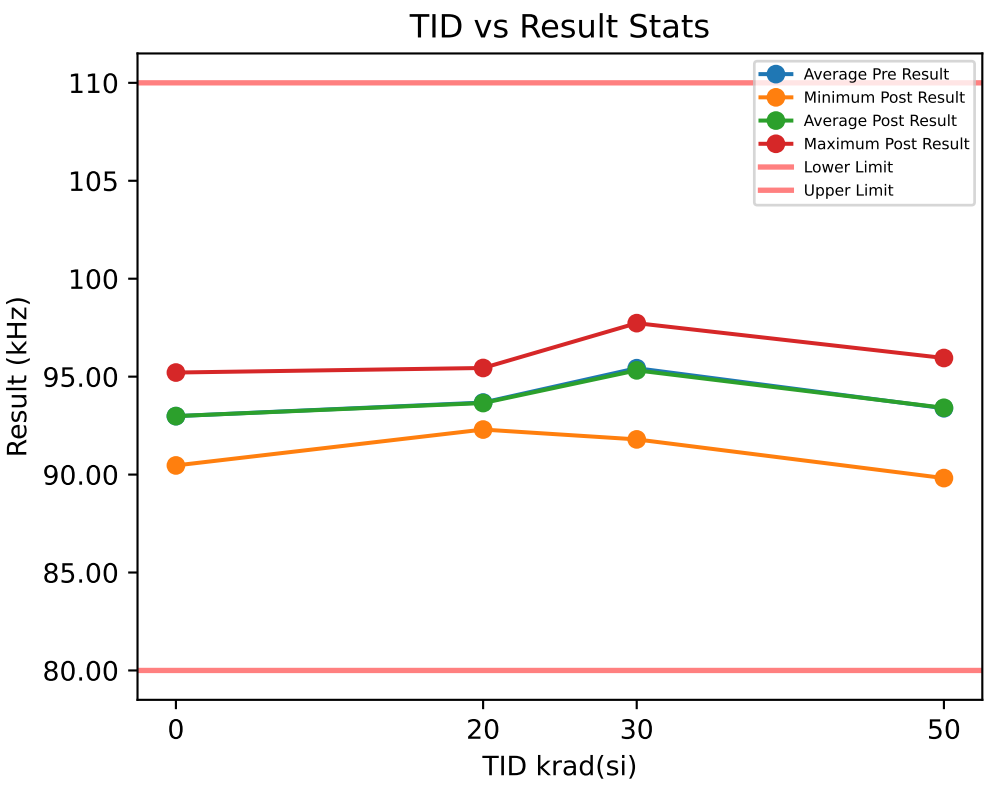
Test Results (Upper Limit = 5.0 ((1/fsw) s))

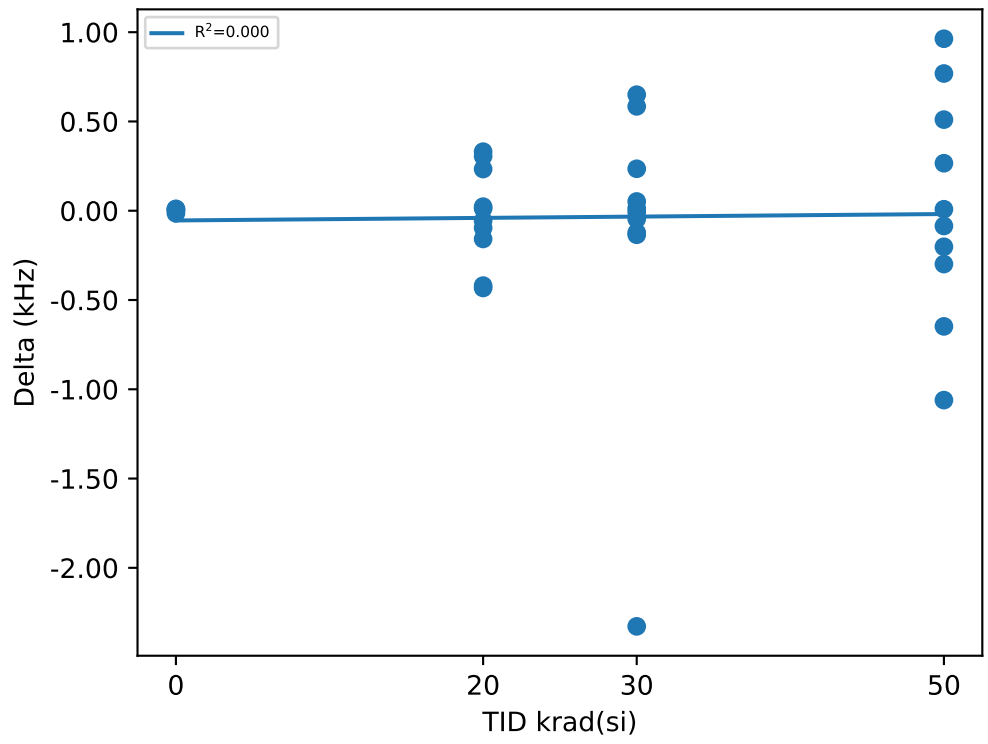
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	2.2984	2.4219	0.1235
2	20	Unbiased	2.0193	2.3763	0.357
3	50	Biased	2.2971	2.2504	-0.0467
4	30	Unbiased	1.9738	2.0028	0.029
5	50	Unbiased	2.5695	2.389	-0.1805
6	30	Biased	2.0178	2.3457	0.3279
7	50	Biased	2.376	2.5502	0.1742
8	30	Unbiased	1.9994	1.9868	-0.0126
9	20	Unbiased	2.5287	2.0615	-0.4672
10	50	Biased	2.1094	2.3399	0.2305
11	30	Biased	2.3786	2.1956	-0.183
12	0	Correlation	2.1883	2.5631	0.3748
13	0	Correlation	2.3412	2.4678	0.1266
14	50	Unbiased	1.9429	1.9711	0.0282
15	20	Biased	2.1386	2.501	0.3624
16	20	Unbiased	2.0117	2.0365	0.0248
17	20	Biased	2.1727	1.9936	-0.1791
18	20	Unbiased	2.1165	2.0543	-0.0622
19	20	Biased	2.2994	2.328	0.0286
20	50	Unbiased	1.911	2.1949	0.2839
21	0	Correlation	2.2678	1.9711	-0.2967
22	50	Unbiased	2.0296	2.0519	0.0223
23	0	Correlation	2.1192	2.0614	-0.0578
24	20	Biased	2.0628	2.0527	-0.0101
26	50	Biased	2.1517	2.0496	-0.1021
27	30	Unbiased	2.4183	2.1272	-0.2911
28	30	Biased	1.9974	2.2254	0.228
29	30	Unbiased	2.3157	2.2572	-0.0585
30	20	Biased	1.9233	2.4026	0.4793
31	30	Unbiased	2.3129	1.8224	-0.4905
33	30	Biased	2.309	2.4499	0.1409
34	50	Unbiased	1.9699	2.5211	0.5512
35	20	Unbiased	2.469	2.4399	-0.0291
41	30	Biased	2.4224	2.1595	-0.2629

Test Statistics ((1/fsw) s)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.1192	2.2291	2.3412	0.096275	1.9711	2.2658	2.5631	0.29315	-0.2967	0.036725	0.3748	0.2843
20	1.9233	2.1742	2.5287	0.19961	1.9936	2.2246	2.501	0.20056	-0.4672	0.05044	0.4793	0.28278
30	1.9738	2.2145	2.4224	0.19165	1.8224	2.1573	2.4499	0.18355	-0.4905	-0.05728	0.3279	0.25362
50	1.911	2.1656	2.5695	0.21522	1.9711	2.274	2.5502	0.20413	-0.1805	0.10845	0.5512	0.21396

Device Test: 20.15 LEVEL|FREQ/RT/4.5/4.5/0/0/4.5/100kHz//@FSW_EXT_RT_A





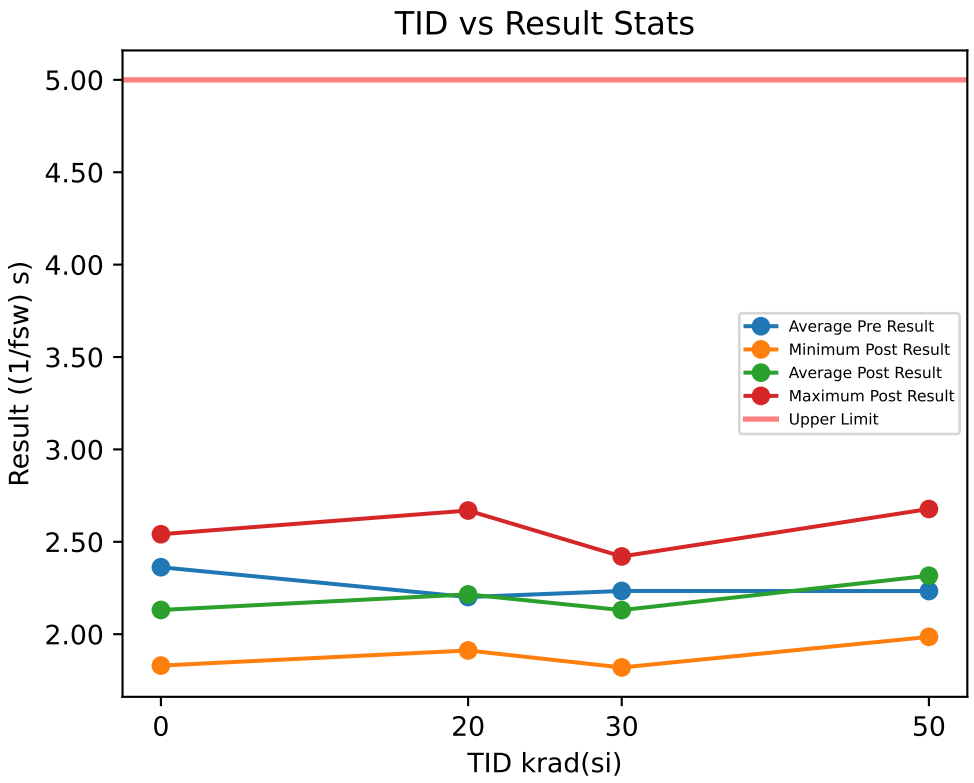
Test Results (Lower Limit = 80.0, Upper Limit = 110.0 (kHz))

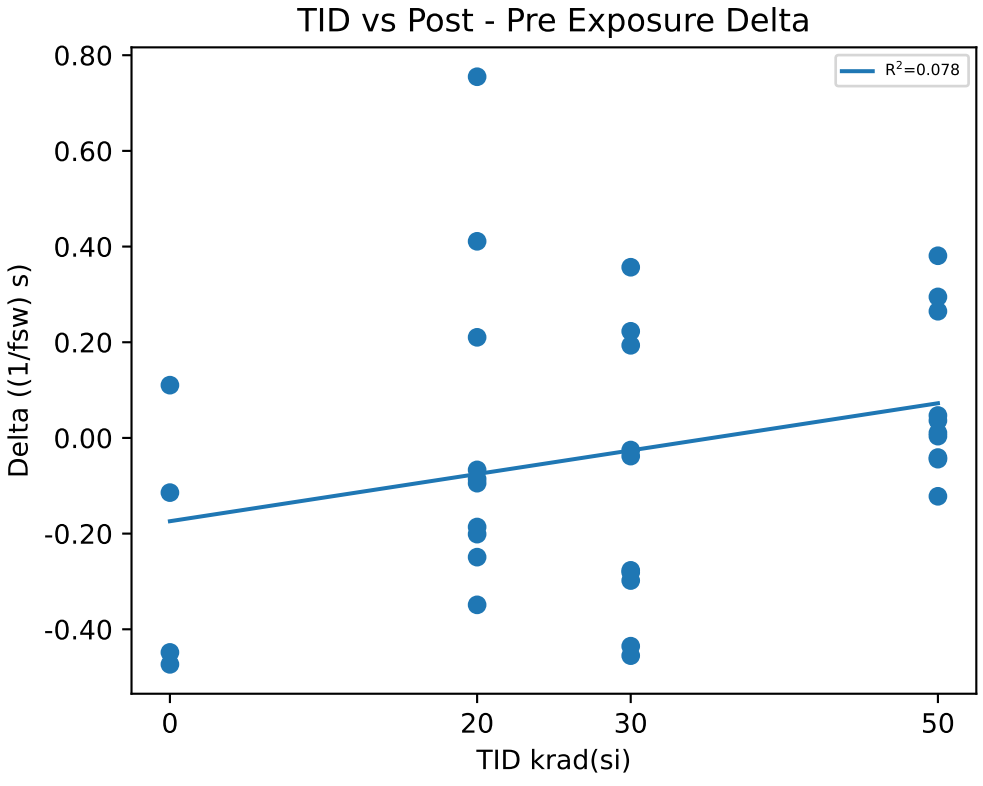
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	91.894	91.596	-0.2987
2	20	Unbiased	93.948	93.892	-0.0558
3	50	Biased	94.445	94.955	0.5103
4	30	Unbiased	95.78	95.646	-0.1345
5	50	Unbiased	90.882	89.821	-1.0606
6	30	Biased	93.641	94.226	0.5846
7	50	Biased	94.205	94.003	-0.2019
8	30	Unbiased	94.94	94.992	0.0519
9	20	Unbiased	92.395	92.299	-0.096
10	50	Biased	95.223	95.489	0.2661
11	30	Biased	95.902	96.552	0.6499
12	0	Correlation	90.458	90.467	0.009
13	0	Correlation	93.126	93.136	0.0102
14	50	Unbiased	96.038	95.952	-0.0854
15	20	Biased	93.423	93.728	0.3052
16	20	Unbiased	92.774	93.105	0.3308
17	20	Biased	95.862	95.442	-0.4194
18	20	Unbiased	94.078	93.646	-0.4326
19	20	Biased	93.548	93.39	-0.1581
20	50	Unbiased	93.269	92.622	-0.6477
21	0	Correlation	93.144	93.129	-0.0144
22	50	Unbiased	92.824	92.833	0.0084
23	0	Correlation	95.209	95.21	0.0012
24	20	Biased	93.85	93.873	0.0228
26	50	Biased	93.674	94.442	0.7686
27	30	Unbiased	92.993	92.947	-0.0458
28	30	Biased	97.717	97.731	0.0138
29	30	Unbiased	97.773	97.65	-0.1224
30	20	Biased	93.11	93.343	0.2335
31	30	Unbiased	96.891	96.883	-0.008
33	30	Biased	94.553	94.788	0.235
34	50	Unbiased	91.413	92.376	0.9633
35	20	Unbiased	93.792	93.805	0.0124
41	30	Biased	94.124	91.796	-2.3278

Test Statistics (kHz)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	90.458	92.984	95.209	1.9473	90.467	92.985	95.21	1.9437	-0.0144	0.0015	0.0102	0.011326
20	92.395	93.678	95.862	0.93757	92.299	93.652	95.442	0.79121	-0.4326	-0.02572	0.3308	0.26906
30	92.993	95.431	97.773	1.6686	91.796	95.321	97.731	1.9706	-2.3278	-0.11033	0.6499	0.82694
50	90.882	93.387	96.038	1.6666	89.821	93.409	95.952	1.9085	-1.0606	0.02224	0.9633	0.62598

Device Test: 20.150 FREQ|DETECTION/RT/14/14/0/0/5/100kHz//@T_INT_CLK_DET





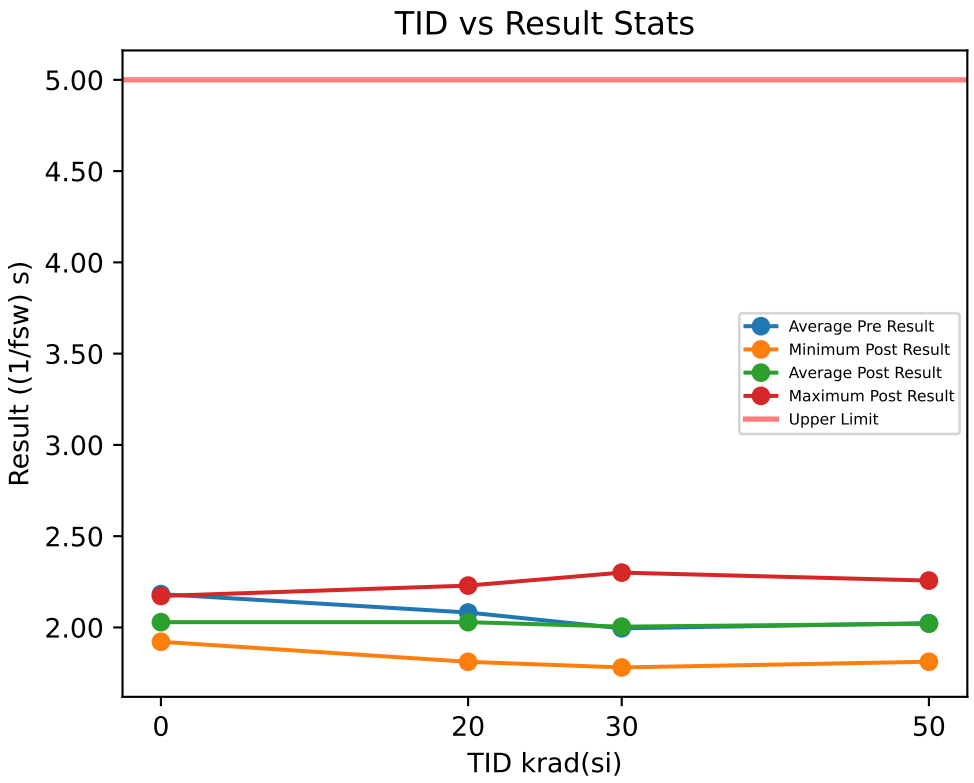
Test Results (Upper Limit = 5.0 ((1/fsw) s))

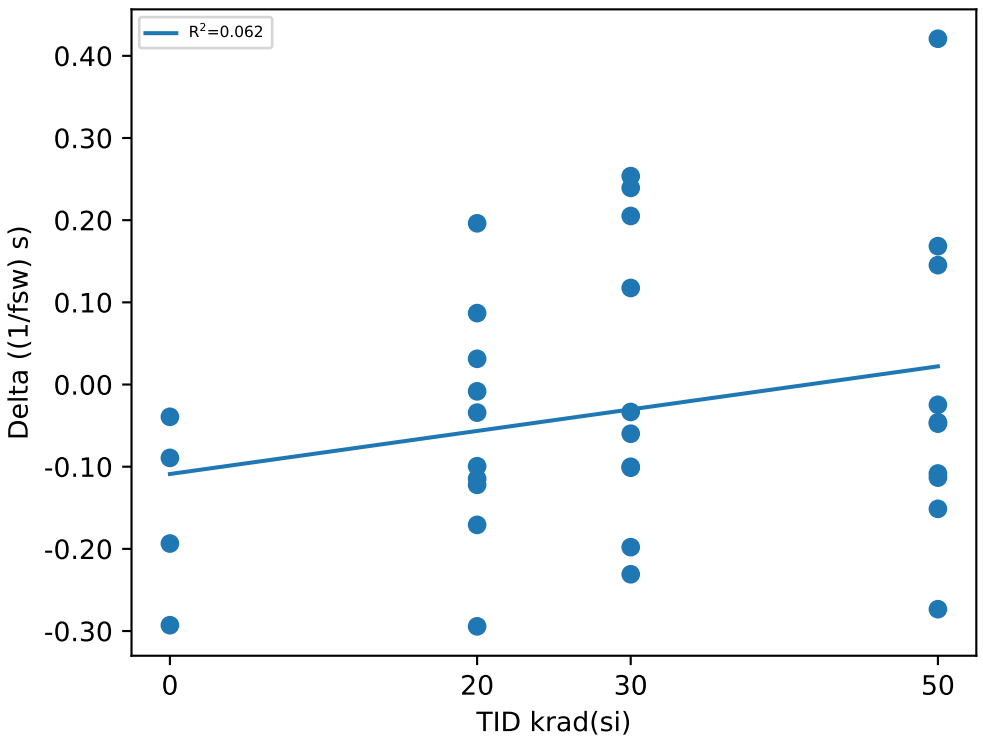
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	2.5437	2.5474	0.0037
2	20	Unbiased	1.9212	2.3322	0.411
3	50	Biased	2.2968	2.6776	0.3808
4	30	Unbiased	2.1732	1.8964	-0.2768
5	50	Unbiased	2.4811	2.4401	-0.041
6	30	Biased	2.1197	2.3426	0.2229
7	50	Biased	2.4421	2.4526	0.0105
8	30	Unbiased	2.1181	1.82	-0.2981
9	20	Unbiased	2.3704	2.1842	-0.1862
10	50	Biased	2.0859	2.3507	0.2648
11	30	Biased	2.3204	2.2951	-0.0253
12	0	Correlation	2.1746	2.2849	0.1103
13	0	Correlation	2.6553	2.541	-0.1143
14	50	Unbiased	2.0981	2.1345	0.0364
15	20	Biased	2.4483	2.1991	-0.2492
16	20	Unbiased	2.1132	2.0275	-0.0857
17	20	Biased	2.2933	1.9444	-0.3489
18	20	Unbiased	2.038	1.9712	-0.0668
19	20	Biased	2.398	2.6083	0.2103
20	50	Unbiased	2.0495	2.0964	0.0469
21	0	Correlation	2.2784	1.8301	-0.4483
22	50	Unbiased	2.0662	2.0218	-0.0444
23	0	Correlation	2.3416	1.8683	-0.4733
24	20	Biased	2.113	1.9119	-0.2011
26	50	Biased	2.1075	1.9855	-0.122
27	30	Unbiased	2.3621	1.9268	-0.4353
28	30	Biased	1.9633	2.3201	0.3568
29	30	Unbiased	2.0699	2.2635	0.1936
30	20	Biased	1.9142	2.6692	0.755
31	30	Unbiased	2.3552	1.9001	-0.4551
33	30	Biased	2.4587	2.4207	-0.038
34	50	Unbiased	2.1647	2.4595	0.2948
35	20	Unbiased	2.4012	2.3066	-0.0946
41	30	Biased	2.3994	2.1185	-0.2809

Test Statistics ((1/fsw) s)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.1746	2.3625	2.6553	0.207	1.8301	2.1311	2.541	0.34222	-0.4733	-0.2314	0.1103	0.2805
20	1.9142	2.2011	2.4483	0.20543	1.9119	2.2155	2.6692	0.2675	-0.3489	0.01438	0.755	0.34332
30	1.9633	2.234	2.4587	0.1656	1.82	2.1304	2.4207	0.22506	-0.4551	-0.10362	0.3568	0.28871
50	2.0495	2.2336	2.5437	0.19079	1.9855	2.3166	2.6776	0.2397	-0.122	0.08305	0.3808	0.16841

Device Test: 20.152 FREQ|DETECTION/RT/4.5/4.5/0/0/4.5/200kHz//@T_INT_CLK_DET





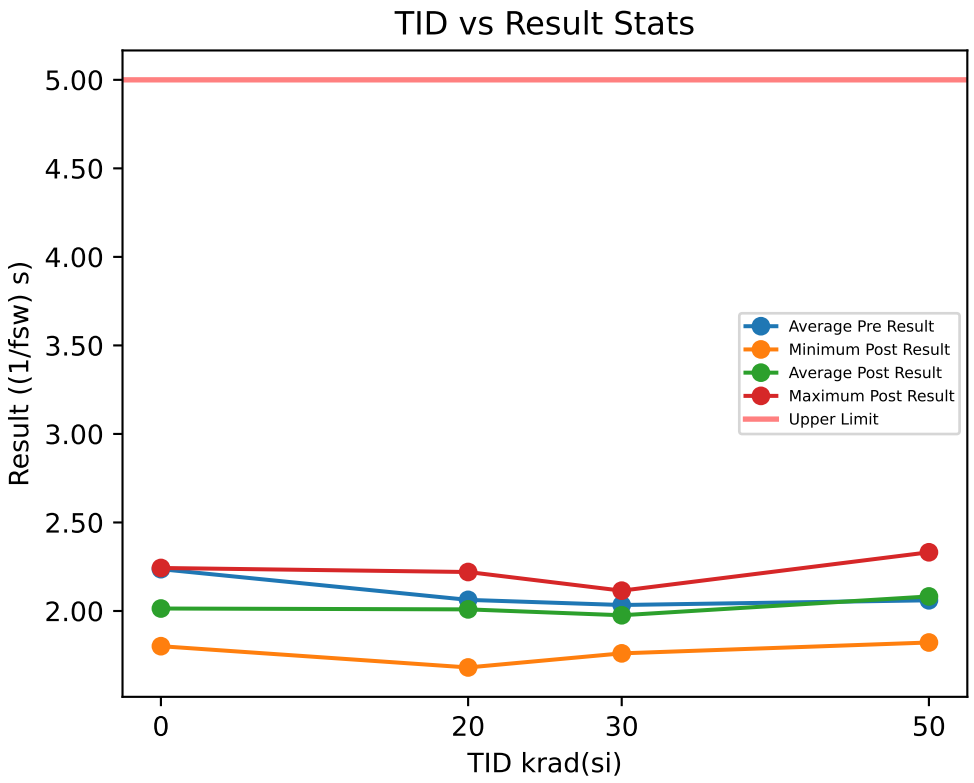
Test Results (Upper Limit = 5.0 ((1/fsw) s))

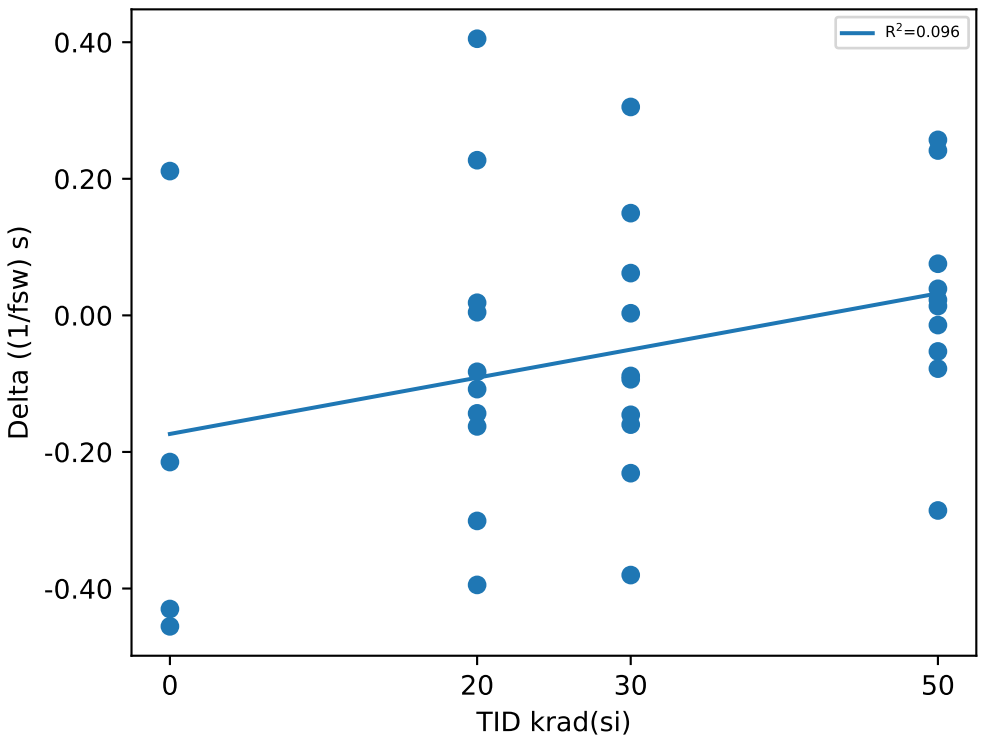
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	2.1427	2.0344	-0.1083
2	20	Unbiased	1.9739	2.1701	0.1962
3	50	Biased	2.1893	2.038	-0.1513
4	30	Unbiased	1.8809	1.7808	-0.1001
5	50	Unbiased	2.2814	2.2567	-0.0247
6	30	Biased	1.7986	2.0379	0.2393
7	50	Biased	2.2653	1.9919	-0.2734
8	30	Unbiased	1.9091	1.8492	-0.0599
9	20	Unbiased	2.2315	1.9372	-0.2943
10	50	Biased	1.8076	2.2284	0.4208
11	30	Biased	2.1181	2.0847	-0.0334
12	0	Correlation	2.0895	2.0502	-0.0393
13	0	Correlation	2.2617	2.1724	-0.0893
14	50	Unbiased	1.858	1.8121	-0.0459
15	20	Biased	2.1816	2.0595	-0.1221
16	20	Unbiased	1.82	1.8117	-0.0083
17	20	Biased	2.1665	2.0671	-0.0994
18	20	Unbiased	1.9233	1.9546	0.0313
19	20	Biased	2.1424	2.2293	0.0869
20	50	Unbiased	1.8742	2.0195	0.1453
21	0	Correlation	2.2145	1.9216	-0.2929
22	50	Unbiased	1.9437	1.8304	-0.1133
23	0	Correlation	2.1652	1.9717	-0.1935
24	20	Biased	1.9859	1.8713	-0.1146
26	50	Biased	1.8918	1.8442	-0.0476
27	30	Unbiased	2.0856	1.8877	-0.1979
28	30	Biased	1.8905	2.0956	0.2051
29	30	Unbiased	1.9412	2.1948	0.2536
30	20	Biased	2.0431	2.0089	-0.0342
31	30	Unbiased	1.9731	1.8719	-0.1012
33	30	Biased	2.1829	2.3004	0.1175
34	50	Unbiased	1.98	2.1484	0.1684
35	20	Unbiased	2.3499	2.1791	-0.1708
41	30	Biased	2.1719	1.941	-0.2309

Test Statistics ((1/fsw) s)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.0895	2.1827	2.2617	0.073586	1.9216	2.029	2.1724	0.10929	-0.2929	-0.15375	-0.0393	0.11284
20	1.82	2.0818	2.3499	0.16024	1.8117	2.0289	2.2293	0.138	-0.2943	-0.05293	0.1962	0.13903
30	1.7986	1.9952	2.1829	0.13467	1.7808	2.0044	2.3004	0.16634	-0.2309	0.00921	0.2536	0.18075
50	1.8076	2.0234	2.2814	0.17906	1.8121	2.0204	2.2567	0.15893	-0.2734	-0.003	0.4208	0.19823

Device Test: 20.154 FREQ|DETECTION/RT/5/5/0/0/5/200kHz//@T_INT_CLK_DET





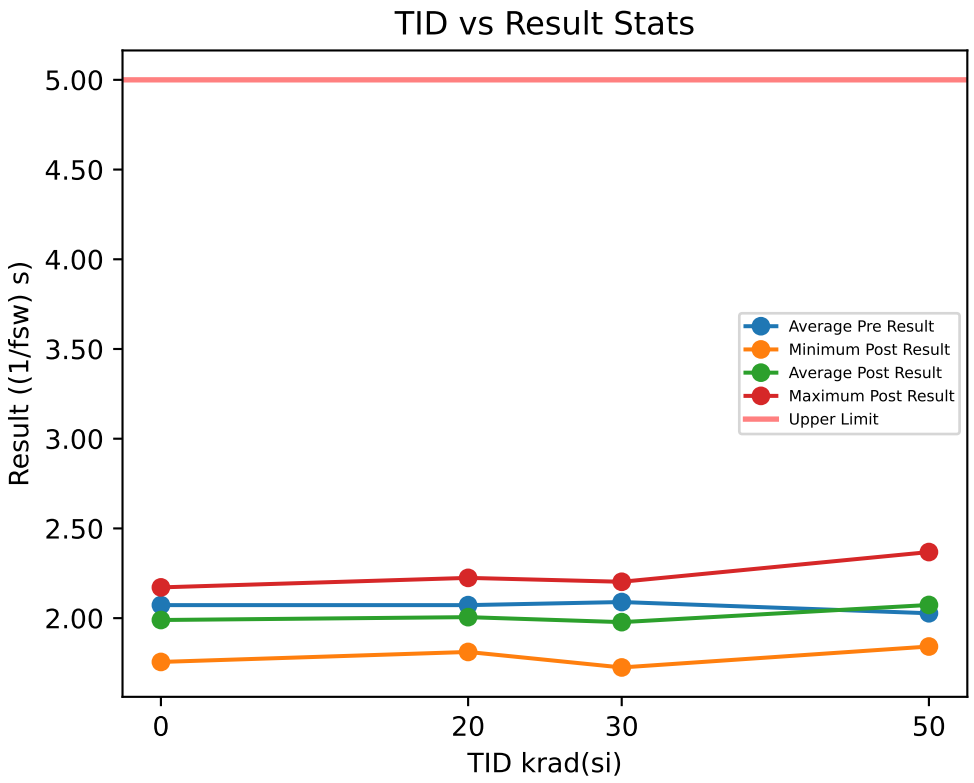
Test Results (Upper Limit = 5.0 ((1/fsw) s))

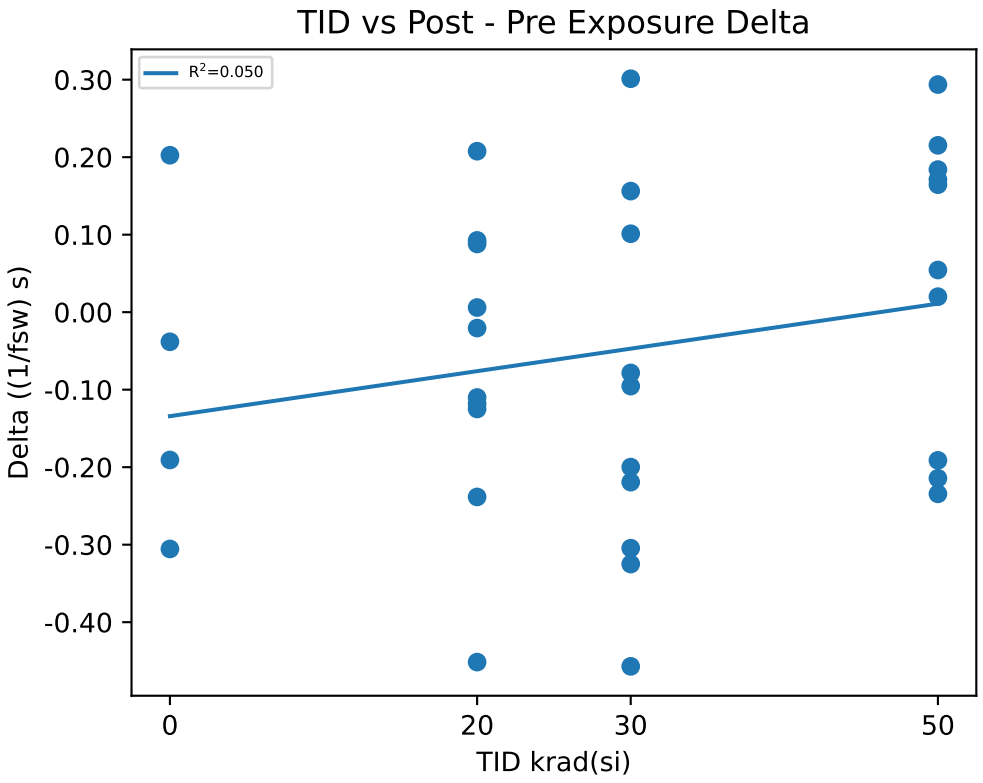
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	2.4153	2.1296	-0.2857
2	20	Unbiased	1.8962	2.1234	0.2272
3	50	Biased	2.202	2.124	-0.078
4	30	Unbiased	2.0068	1.7757	-0.2311
5	50	Unbiased	2.1651	2.204	0.0389
6	30	Biased	1.8313	1.981	0.1497
7	50	Biased	2.0746	2.3316	0.257
8	30	Unbiased	1.9919	1.9032	-0.0887
9	20	Unbiased	2.1538	1.9912	-0.1626
10	50	Biased	2.1011	2.1767	0.0756
11	30	Biased	2.1972	2.1036	-0.0936
12	0	Correlation	2.0317	2.243	0.2113
13	0	Correlation	2.4001	2.1853	-0.2148
14	50	Unbiased	1.8363	1.8221	-0.0142
15	20	Biased	2.3723	2.0713	-0.301
16	20	Unbiased	2.0639	1.9204	-0.1435
17	20	Biased	2.0272	1.9446	-0.0826
18	20	Unbiased	2.0758	1.6811	-0.3947
19	20	Biased	2.2519	2.1439	-0.108
20	50	Unbiased	1.942	1.9647	0.0227
21	0	Correlation	2.2819	1.8265	-0.4554
22	50	Unbiased	1.9593	1.9729	0.0136
23	0	Correlation	2.2312	1.8012	-0.43
24	20	Biased	1.9172	1.9218	0.0046
26	50	Biased	1.9505	1.8977	-0.0528
27	30	Unbiased	2.1334	1.9878	-0.1456
28	30	Biased	1.8096	2.1148	0.3052
29	30	Unbiased	2.0504	2.0535	0.0031
30	20	Biased	1.8151	2.2202	0.4051
31	30	Unbiased	2.141	1.7607	-0.3803
33	30	Biased	2.1776	2.0176	-0.16
34	50	Unbiased	1.9576	2.199	0.2414
35	20	Unbiased	2.0551	2.0736	0.0185
41	30	Biased	1.9991	2.061	0.0619

Test Statistics ((1/fsw) s)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.0317	2.2362	2.4001	0.15362	1.8012	2.014	2.243	0.23254	-0.4554	-0.22223	0.2113	0.30851
20	1.8151	2.0629	2.3723	0.16721	1.6811	2.0091	2.2202	0.15325	-0.3947	-0.0537	0.4051	0.2355
30	1.8096	2.0338	2.1972	0.135	1.7607	1.9759	2.1148	0.12581	-0.3803	-0.05794	0.3052	0.19644
50	1.8363	2.0604	2.4153	0.16863	1.8221	2.0822	2.3316	0.16022	-0.2857	0.02185	0.257	0.1557

Device Test: 20.156 FREQ|DETECTION/RT/12/12/0/0/5/200kHz//@T_INT_CLK_DET





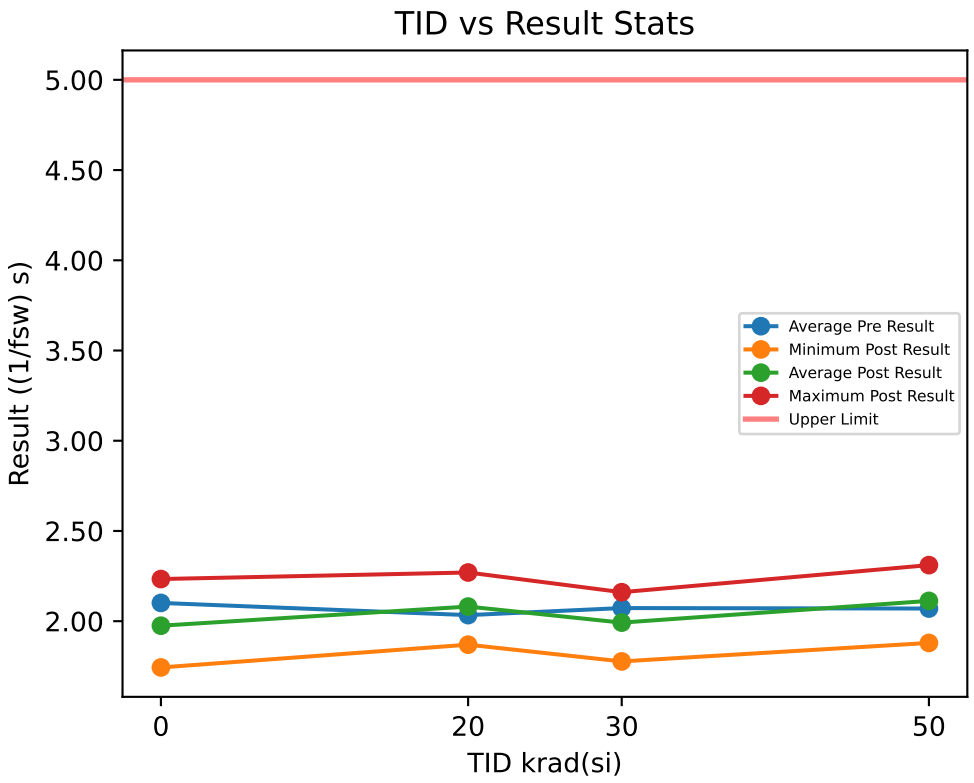
Test Results (Upper Limit = 5.0 ((1/fsw) s))

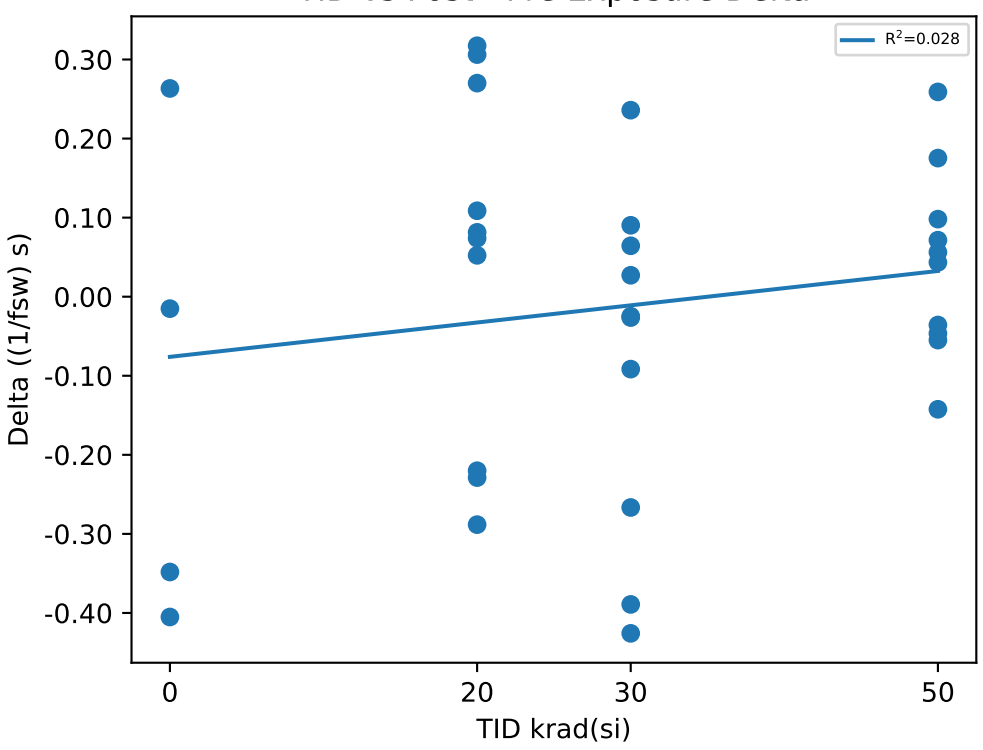
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	2.3476	2.1132	-0.2344
2	20	Unbiased	2.0167	2.2244	0.2077
3	50	Biased	2.0919	2.1463	0.0544
4	30	Unbiased	1.9251	1.7252	-0.1999
5	50	Unbiased	2.153	2.3683	0.2153
6	30	Biased	1.8291	2.1303	0.3012
7	50	Biased	2.2122	1.9979	-0.2143
8	30	Unbiased	2.0428	1.8235	-0.2193
9	20	Unbiased	2.3351	1.8836	-0.4515
10	50	Biased	1.8598	2.0438	0.184
11	30	Biased	2.1228	2.0444	-0.0784
12	0	Correlation	1.9689	2.1714	0.2025
13	0	Correlation	2.1973	2.1591	-0.0382
14	50	Unbiased	1.7866	1.9511	0.1645
15	20	Biased	2.071	2.159	0.088
16	20	Unbiased	1.9744	1.8562	-0.1182
17	20	Biased	2.1224	1.884	-0.2384
18	20	Unbiased	1.9029	1.9089	0.006
19	20	Biased	2.24	2.1299	-0.1101
20	50	Unbiased	1.9125	2.0837	0.1712
21	0	Correlation	2.0614	1.7559	-0.3055
22	50	Unbiased	2.0261	2.0461	0.02
23	0	Correlation	2.0628	1.8721	-0.1907
24	20	Biased	1.9365	1.8116	-0.1249
26	50	Biased	2.0331	1.8419	-0.1912
27	30	Unbiased	2.2098	1.7528	-0.457
28	30	Biased	1.9133	2.0695	0.1562
29	30	Unbiased	2.3372	2.0327	-0.3045
30	20	Biased	1.9796	2.0722	0.0926
31	30	Unbiased	2.2566	1.9316	-0.325
33	30	Biased	2.1015	2.2027	0.1012
34	50	Unbiased	1.8489	2.1426	0.2937
35	20	Unbiased	2.1467	2.1262	-0.0205
41	30	Biased	2.1601	2.0647	-0.0954

Test Statistics ((1/fsw) s)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.9689	2.0726	2.1973	0.094031	1.7559	1.9896	2.1714	0.20833	-0.3055	-0.082975	0.2025	0.21956
20	1.9029	2.0725	2.3351	0.1389	1.8116	2.0056	2.2244	0.15085	-0.4515	-0.06693	0.2077	0.18782
30	1.8291	2.0898	2.3372	0.16263	1.7252	1.9777	2.2027	0.16249	-0.457	-0.11209	0.3012	0.2381
50	1.7866	2.0272	2.3476	0.17882	1.8419	2.0735	2.3683	0.1393	-0.2344	0.04632	0.2937	0.19498

Device Test: 20.158 FREQ|DETECTION/RT/14/14/0/0/5/200kHz//@T_INT_CLK_DET





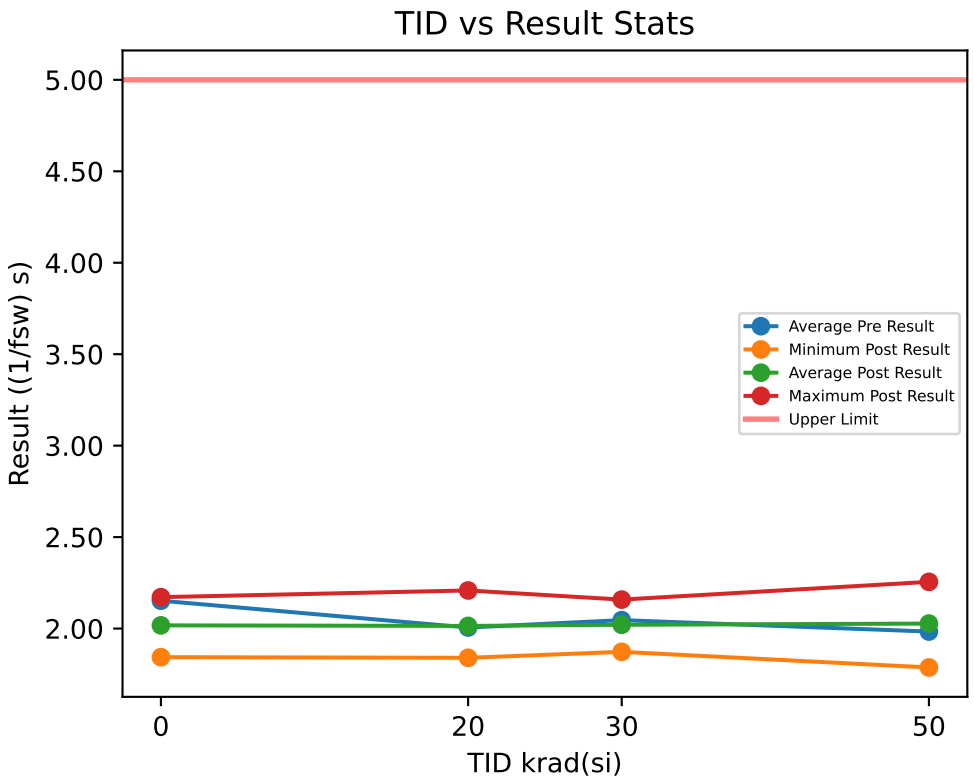
Test Results (Upper Limit = 5.0 ((1/fsw) s))

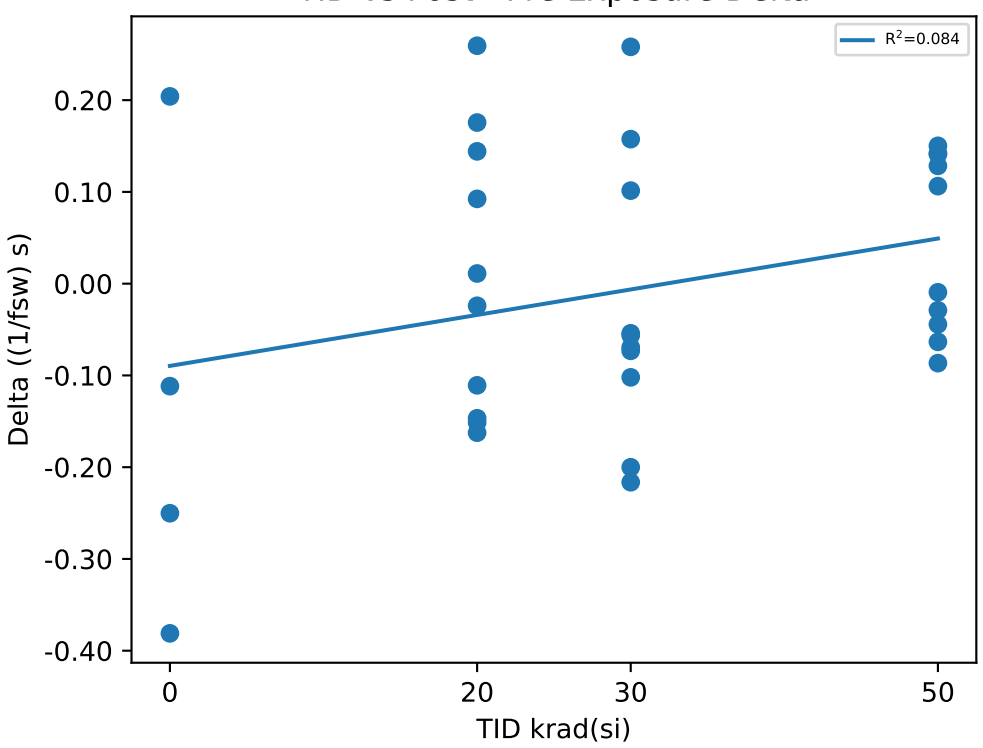
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	2.1275	2.3028	0.1753
2	20	Unbiased	1.8871	2.1572	0.2701
3	50	Biased	2.3762	2.2338	-0.1424
4	30	Unbiased	1.9653	1.9406	-0.0247
5	50	Unbiased	2.2392	2.3107	0.0715
6	30	Biased	1.8563	2.0922	0.2359
7	50	Biased	2.1703	2.1345	-0.0358
8	30	Unbiased	1.9123	1.9394	0.0271
9	20	Unbiased	2.2251	1.9963	-0.2288
10	50	Biased	1.8636	2.1226	0.259
11	30	Biased	2.0969	2.0705	-0.0264
12	0	Correlation	1.8767	2.1401	0.2634
13	0	Correlation	2.2487	2.2336	-0.0151
14	50	Unbiased	1.9013	1.9994	0.0981
15	20	Biased	2.1895	2.2634	0.0739
16	20	Unbiased	1.776	2.0934	0.3174
17	20	Biased	2.1581	1.8698	-0.2883
18	20	Unbiased	1.8271	1.8794	0.0523
19	20	Biased	2.1884	2.2698	0.0814
20	50	Unbiased	2.0828	2.0279	-0.0549
21	0	Correlation	2.1876	1.7825	-0.4051
22	50	Unbiased	1.9927	1.9462	-0.0465
23	0	Correlation	2.0918	1.7436	-0.3482
24	20	Biased	1.9916	2.1003	0.1087
26	50	Biased	1.836	1.8794	0.0434
27	30	Unbiased	2.1949	1.9283	-0.2666
28	30	Biased	2.0352	2.0996	0.0644
29	30	Unbiased	2.0963	2.0047	-0.0916
30	20	Biased	1.827	2.1332	0.3062
31	30	Unbiased	2.2029	1.7771	-0.4258
33	30	Biased	2.0704	2.1607	0.0903
34	50	Unbiased	2.1114	2.1676	0.0562
35	20	Unbiased	2.2669	2.0468	-0.2201
41	30	Biased	2.2973	1.9081	-0.3892

Test Statistics ((1/fsw) s)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.8767	2.1012	2.2487	0.163	1.7436	1.9749	2.2336	0.24815	-0.4051	-0.12625	0.2634	0.31156
20	1.776	2.0337	2.2669	0.19142	1.8698	2.081	2.2698	0.13807	-0.2883	0.04728	0.3174	0.22501
30	1.8563	2.0728	2.2973	0.13702	1.7771	1.9921	2.1607	0.11503	-0.4258	-0.08066	0.2359	0.2153
50	1.836	2.0701	2.3762	0.17302	1.8794	2.1125	2.3107	0.14749	-0.1424	0.04239	0.259	0.11849

Device Test: 20.160 FREQ|DETECTION/RT/4.5/4.5/0/0/4.5/500kHz//@T_INT_CLK_DET





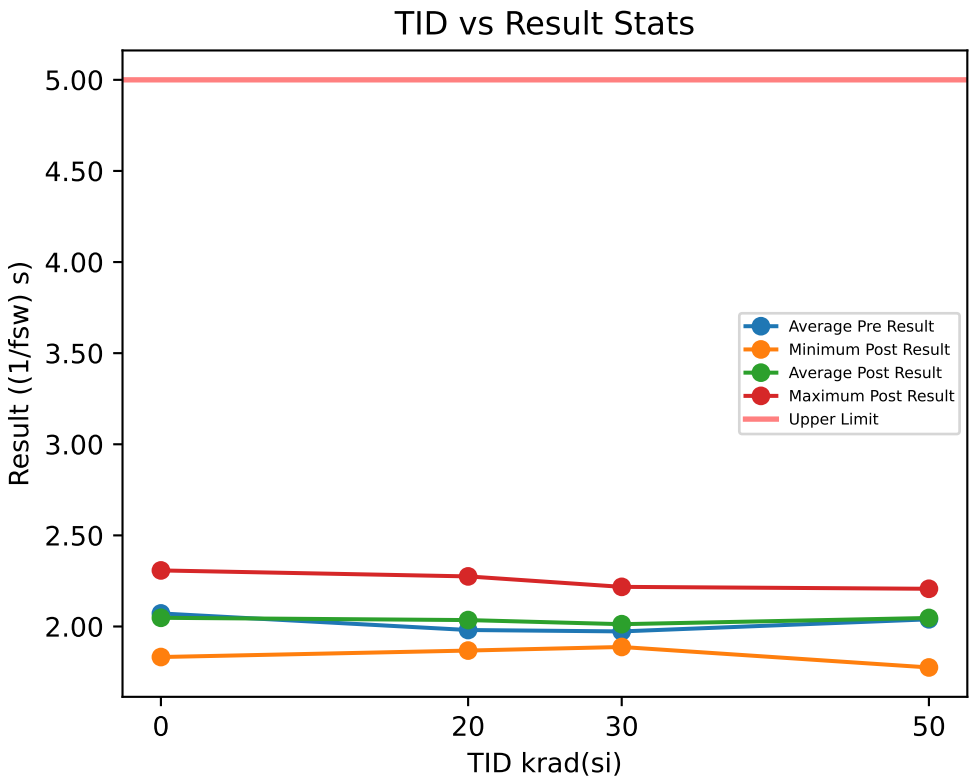
Test Results (Upper Limit = 5.0 ((1/fsw) s))

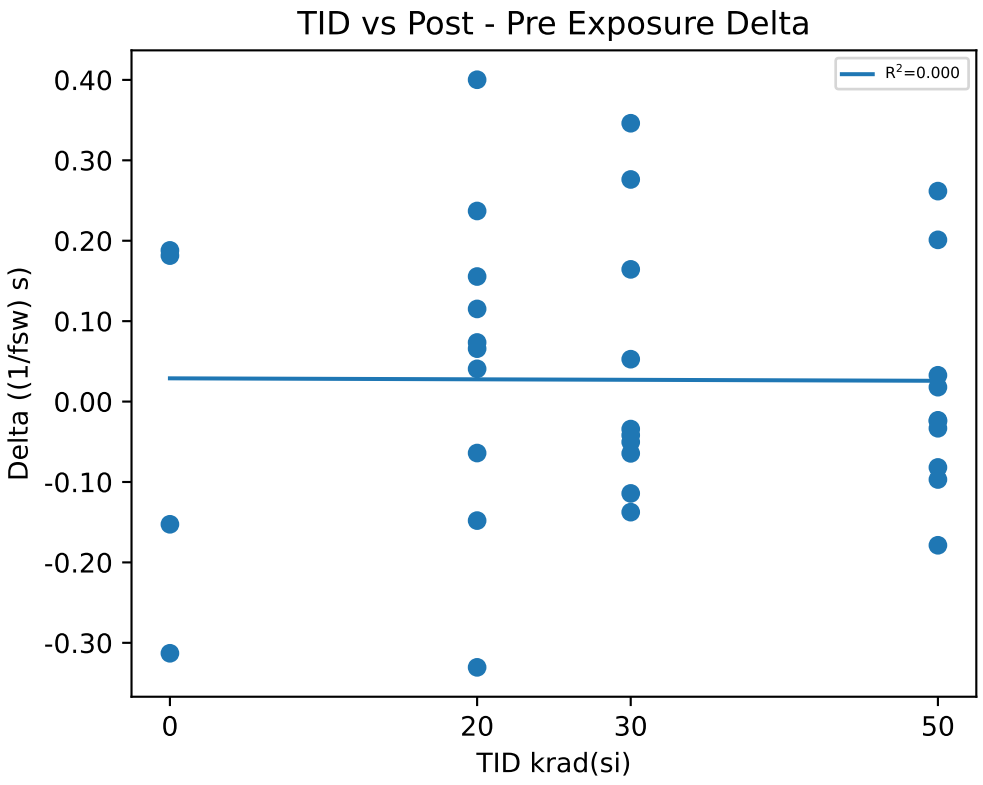
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	2.1269	2.2553	0.1284
2	20	Unbiased	2.0189	2.1631	0.1442
3	50	Biased	2.0417	2.1839	0.1422
4	30	Unbiased	1.9683	2.0697	0.1014
5	50	Unbiased	2.0606	2.0512	-0.0094
6	30	Biased	1.9422	2.0997	0.1575
7	50	Biased	2.0616	2.2118	0.1502
8	30	Unbiased	1.9993	1.93	-0.0693
9	20	Unbiased	2.0863	1.9396	-0.1467
10	50	Biased	2.0253	1.9963	-0.029
11	30	Biased	2.081	2.0247	-0.0563
12	0	Correlation	1.9676	2.1717	0.2041
13	0	Correlation	2.2034	2.0917	-0.1117
14	50	Unbiased	1.9418	1.8552	-0.0866
15	20	Biased	2.0565	2.0676	0.0111
16	20	Unbiased	1.8721	1.9645	0.0924
17	20	Biased	2.0113	1.86	-0.1513
18	20	Unbiased	2.0259	1.8635	-0.1624
19	20	Biased	2.1286	2.1045	-0.0241
20	50	Unbiased	1.8316	1.7873	-0.0443
21	0	Correlation	2.2133	1.9631	-0.2502
22	50	Unbiased	1.8362	1.9772	0.141
23	0	Correlation	2.2246	1.8435	-0.3811
24	20	Biased	1.9509	1.8401	-0.1108
26	50	Biased	1.9554	1.892	-0.0634
27	30	Unbiased	2.0505	1.9964	-0.0541
28	30	Biased	1.9002	2.1583	0.2581
29	30	Unbiased	2.246	2.0296	-0.2164
30	20	Biased	1.8733	2.1326	0.2593
31	30	Unbiased	2.0728	1.8727	-0.2001
33	30	Biased	2.1178	2.0157	-0.1021
34	50	Unbiased	1.9551	2.0614	0.1063
35	20	Unbiased	2.0327	2.2083	0.1756
41	30	Biased	2.0828	2.0096	-0.0732

Test Statistics ((1/fsw) s)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.9676	2.1522	2.2246	0.12339	1.8435	2.0175	2.1717	0.14436	-0.3811	-0.13472	0.2041	0.25124
20	1.8721	2.0057	2.1286	0.084265	1.8401	2.0144	2.2083	0.13732	-0.1624	0.00873	0.2593	0.1529
30	1.9002	2.0461	2.246	0.099288	1.8727	2.0206	2.1583	0.08065	-0.2164	-0.02545	0.2581	0.15231
50	1.8316	1.9836	2.1269	0.097666	1.7873	2.0272	2.2553	0.1568	-0.0866	0.04354	0.1502	0.097697

Device Test: 20.162 FREQ|DETECTION/RT/5/5/0/0/5/500kHz//@T_INT_CLK_DET





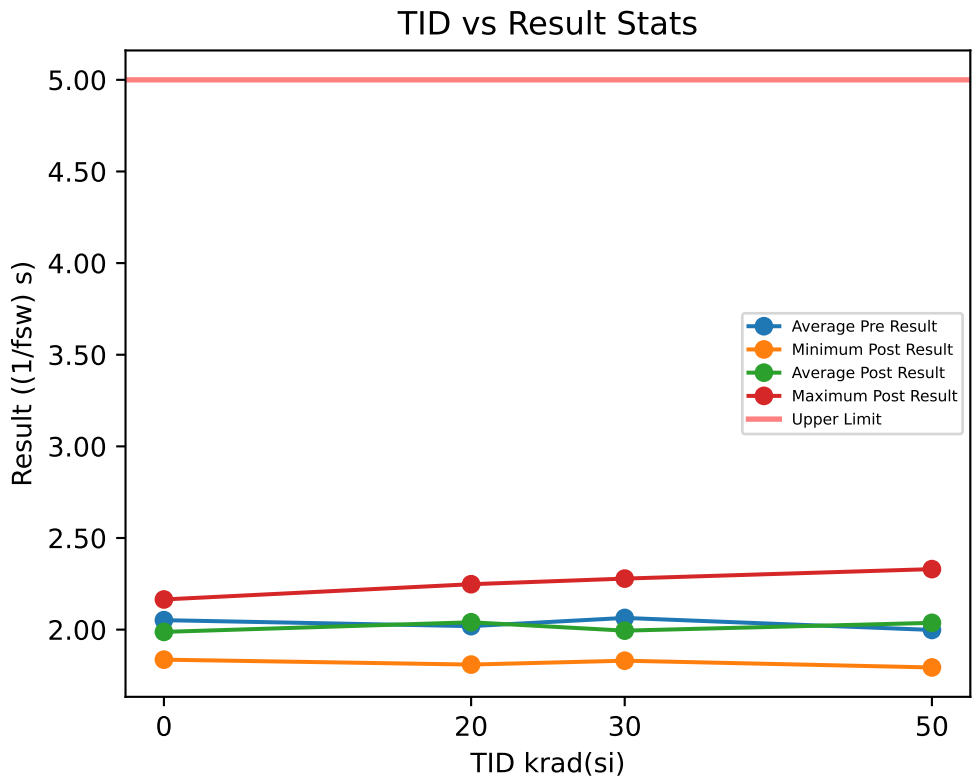
Test Results (Upper Limit = 5.0 ((1/fsw) s))

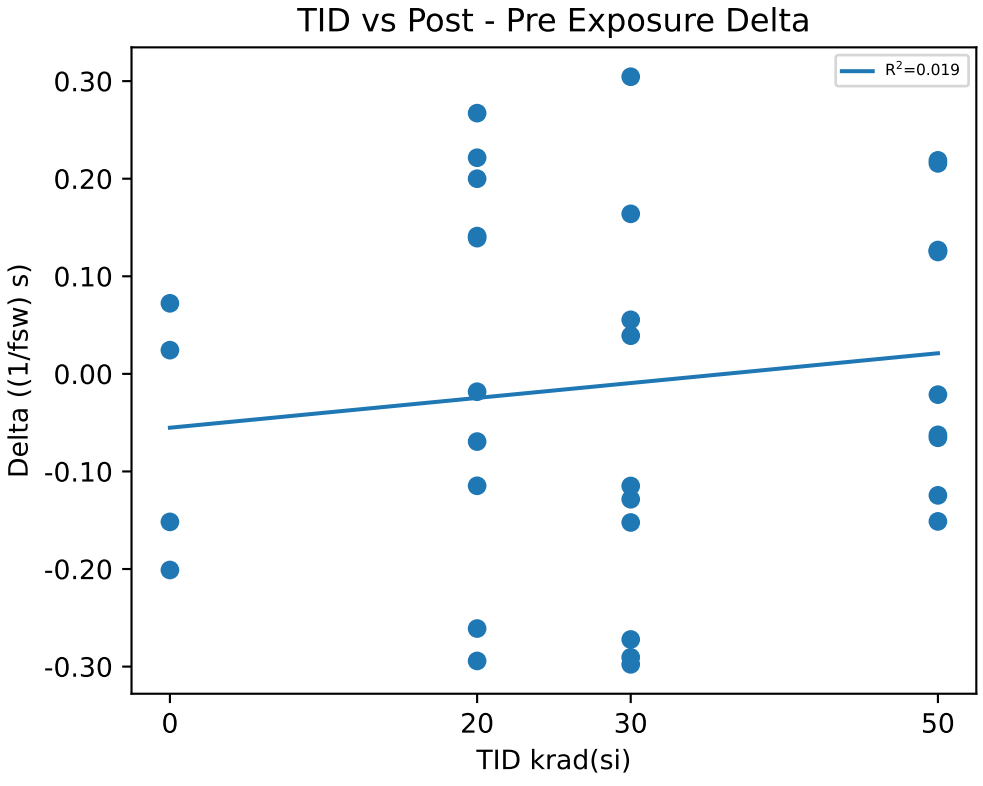
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	2.2402	2.207	-0.0332
2	20	Unbiased	1.8747	2.2749	0.4002
3	50	Biased	2.1236	2.1003	-0.0233
4	30	Unbiased	1.7767	2.0529	0.2762
5	50	Unbiased	2.3521	2.1734	-0.1787
6	30	Biased	1.837	2.1831	0.3461
7	50	Biased	2.102	2.1347	0.0327
8	30	Unbiased	1.9379	1.8876	-0.0503
9	20	Unbiased	2.2255	1.895	-0.3305
10	50	Biased	1.918	2.1191	0.2011
11	30	Biased	2.0167	1.9749	-0.0418
12	0	Correlation	2.1262	2.3077	0.1815
13	0	Correlation	1.9268	2.1148	0.188
14	50	Unbiased	1.9443	1.8624	-0.0819
15	20	Biased	2.1265	2.1923	0.0658
16	20	Unbiased	1.9377	1.9784	0.0407
17	20	Biased	2.1092	1.9612	-0.148
18	20	Unbiased	1.7527	1.8679	0.1152
19	20	Biased	2.1903	2.1263	-0.064
20	50	Unbiased	2.0697	2.0876	0.0179
21	0	Correlation	2.1454	1.8324	-0.313
22	50	Unbiased	1.865	1.8407	-0.0243
23	0	Correlation	2.0885	1.9359	-0.1526
24	20	Biased	1.7145	1.9515	0.237
26	50	Biased	1.8721	1.7752	-0.0969
27	30	Unbiased	2.0472	2.013	-0.0342
28	30	Biased	1.8593	2.0237	0.1644
29	30	Unbiased	2.0255	1.9113	-0.1142
30	20	Biased	1.9286	2.0841	0.1555
31	30	Unbiased	2.0432	1.9057	-0.1375
33	30	Biased	2.1648	2.2175	0.0527
34	50	Unbiased	1.9066	2.1683	0.2617
35	20	Unbiased	1.9473	2.0208	0.0735
41	30	Biased	2.0215	1.9571	-0.0644

Test Statistics ((1/fsw) s)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.9268	2.0717	2.1454	0.099466	1.8324	2.0477	2.3077	0.20893	-0.313	-0.024025	0.188	0.24982
20	1.7145	1.9807	2.2255	0.17682	1.8679	2.0352	2.2749	0.13182	-0.3305	0.05454	0.4002	0.20294
30	1.7767	1.973	2.1648	0.11805	1.8876	2.0127	2.2175	0.11285	-0.1375	0.0397	0.3461	0.16722
50	1.865	2.0394	2.3521	0.16662	1.7752	2.0469	2.207	0.15783	-0.1787	0.00751	0.2617	0.13334

Device Test: 20.164 FREQ|DETECTION/RT/12/12/0/0/5/500kHz//@T_INT_CLK_DET





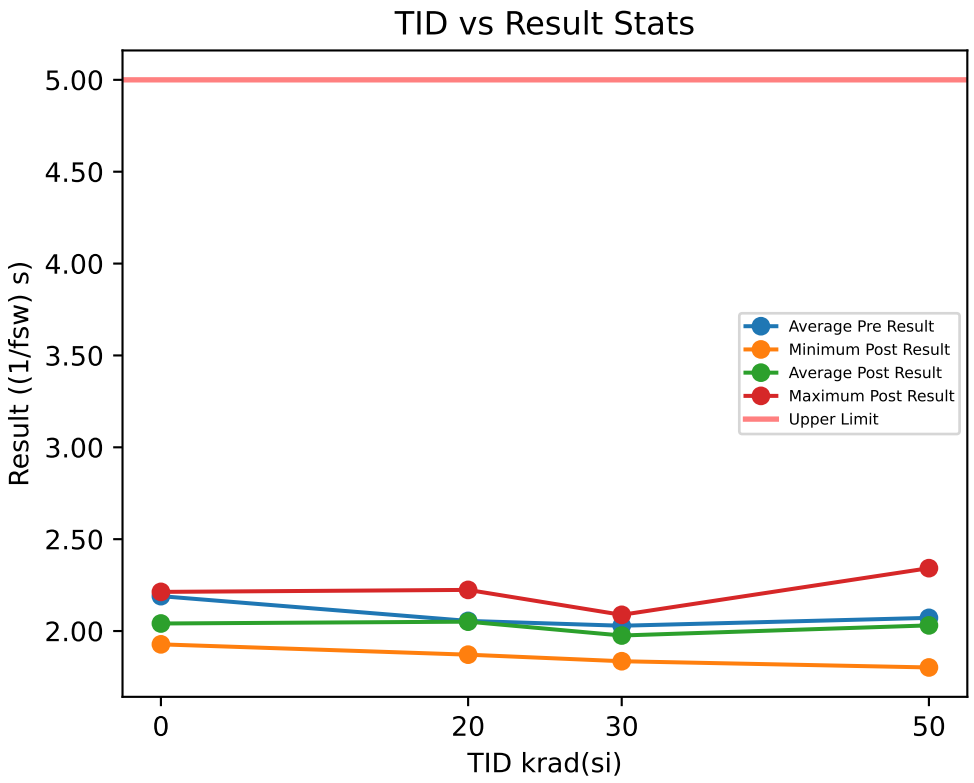
Test Results (Upper Limit = 5.0 ((1/fsw) s))

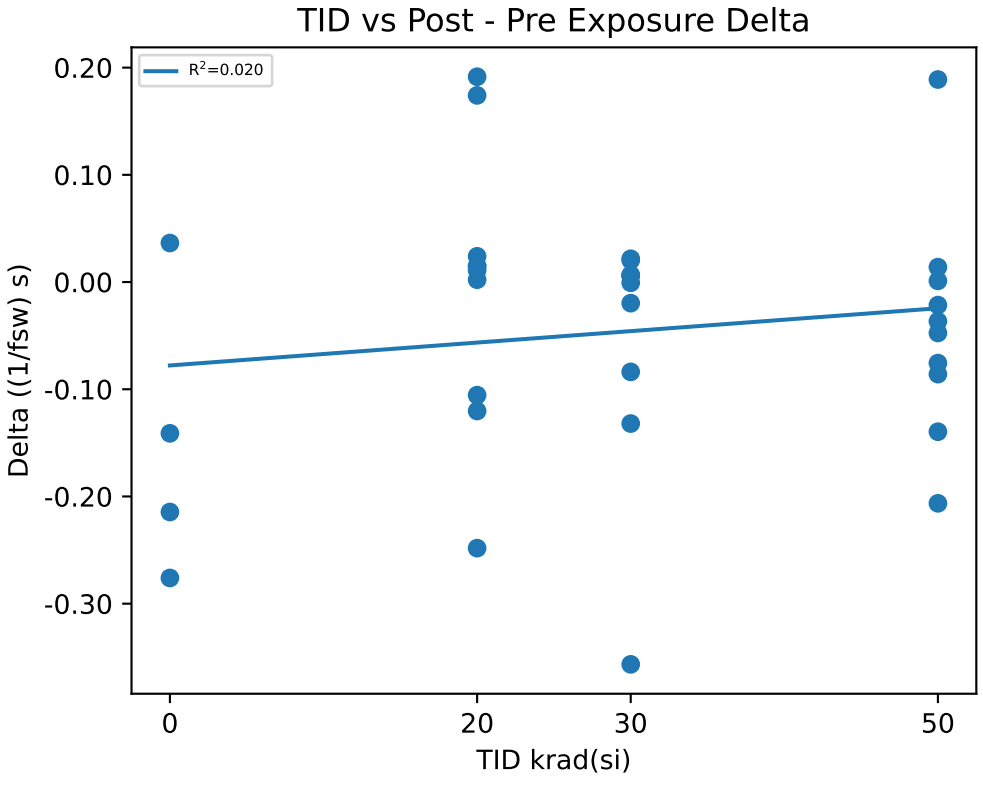
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	2.0556	2.1817	0.1261
2	20	Unbiased	1.876	2.1432	0.2672
3	50	Biased	2.1239	1.9727	-0.1512
4	30	Unbiased	1.9761	1.8612	-0.1149
5	50	Unbiased	2.1145	2.3302	0.2157
6	30	Biased	1.974	2.2785	0.3045
7	50	Biased	2.1923	2.1298	-0.0625
8	30	Unbiased	1.9236	1.9627	0.0391
9	20	Unbiased	2.2193	1.9583	-0.261
10	50	Biased	1.9013	2.1201	0.2188
11	30	Biased	2.1231	1.9946	-0.1285
12	0	Correlation	1.9353	2.0076	0.0723
13	0	Correlation	2.1403	2.1646	0.0243
14	50	Unbiased	2.0463	1.9218	-0.1245
15	20	Biased	2.0466	2.0283	-0.0183
16	20	Unbiased	1.9367	2.0758	0.1391
17	20	Biased	2.1035	1.8093	-0.2942
18	20	Unbiased	2.058	1.9433	-0.1147
19	20	Biased	2.0478	2.2478	0.2
20	50	Unbiased	1.7819	1.9068	0.1249
21	0	Correlation	2.0938	1.9421	-0.1517
22	50	Unbiased	1.9558	1.8903	-0.0655
23	0	Correlation	2.0372	1.8362	-0.201
24	20	Biased	1.9817	1.9123	-0.0694
26	50	Biased	1.8149	1.7936	-0.0213
27	30	Unbiased	2.3016	2.0111	-0.2905
28	30	Biased	1.8286	1.9926	0.164
29	30	Unbiased	2.0651	2.1205	0.0554
30	20	Biased	1.873	2.0945	0.2215
31	30	Unbiased	2.1027	1.8305	-0.2722
33	30	Biased	2.1395	1.9872	-0.1523
34	50	Unbiased	1.996	2.1229	0.1269
35	20	Unbiased	2.0477	2.1889	0.1412
41	30	Biased	2.2036	1.9059	-0.2977

Test Statistics ((1/fsw) s)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.9353	2.0516	2.1403	0.088283	1.8362	1.9876	2.1646	0.1375	-0.201	-0.064025	0.0723	0.13271
20	1.873	2.019	2.2193	0.106	1.8093	2.0402	2.2478	0.13579	-0.2942	0.02114	0.2672	0.20228
30	1.8286	2.0638	2.3016	0.14047	1.8305	1.9945	2.2785	0.12927	-0.2977	-0.06931	0.3045	0.20445
50	1.7819	1.9983	2.1923	0.13507	1.7936	2.037	2.3302	0.16497	-0.1512	0.03874	0.2188	0.13905

Device Test: 20.166 FREQ|DETECTION/RT/14/14/0/0/5/500kHz//@T_INT_CLK_DET





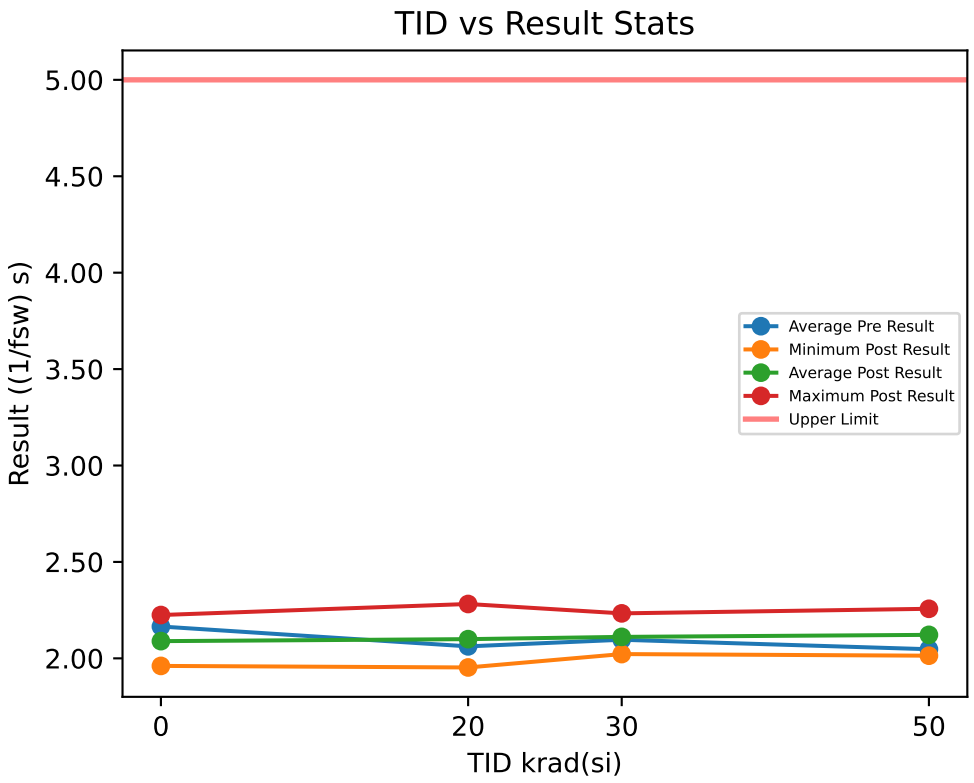
Test Results (Upper Limit = 5.0 ((1/fsw) s))

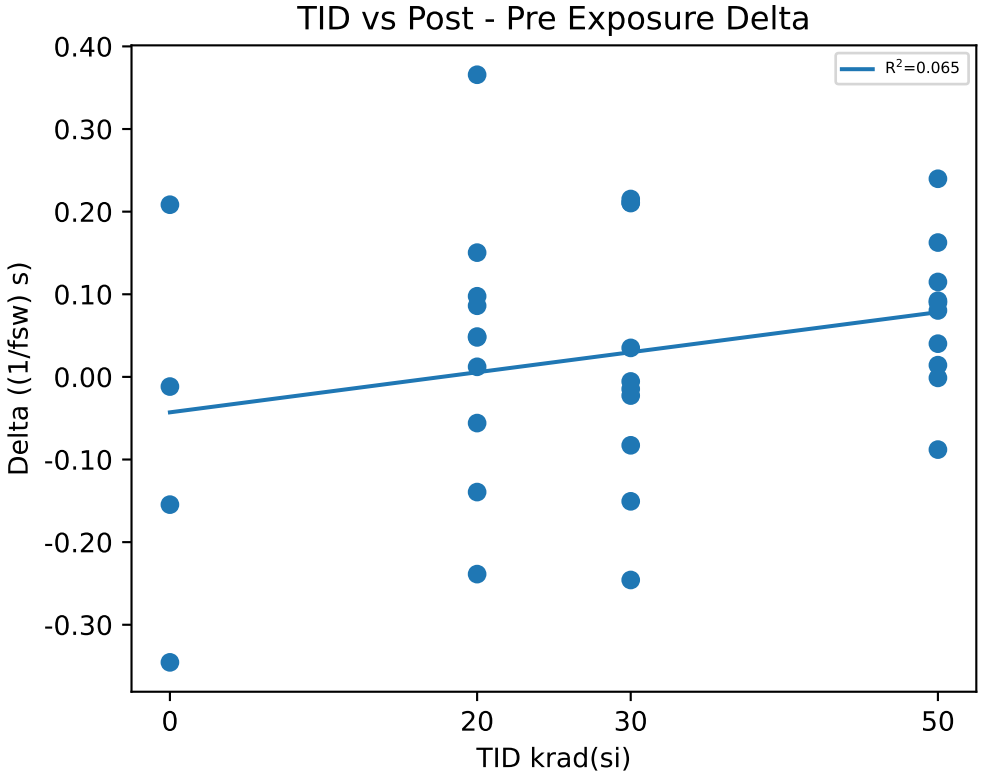
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	2.1759	2.09	-0.0859
2	20	Unbiased	1.9102	2.1017	0.1915
3	50	Biased	2.1354	1.9958	-0.1396
4	30	Unbiased	1.9195	1.8357	-0.0838
5	50	Unbiased	2.3788	2.3422	-0.0366
6	30	Biased	1.9838	1.9905	0.0067
7	50	Biased	2.0201	2.0212	0.0011
8	30	Unbiased	1.8765	1.8823	0.0058
9	20	Unbiased	2.167	2.0467	-0.1203
10	50	Biased	2.0311	2.045	0.0139
11	30	Biased	1.9228	1.9445	0.0217
12	0	Correlation	2.1767	2.2131	0.0364
13	0	Correlation	2.2158	2.0747	-0.1411
14	50	Unbiased	1.9857	1.9101	-0.0756
15	20	Biased	2.1895	2.2046	0.0151
16	20	Unbiased	1.9115	1.9355	0.024
17	20	Biased	2.1242	1.876	-0.2482
18	20	Unbiased	1.9769	1.8714	-0.1055
19	20	Biased	2.0999	2.1021	0.0022
20	50	Unbiased	1.8233	1.8018	-0.0215
21	0	Correlation	2.2036	1.9276	-0.276
22	50	Unbiased	1.9881	1.9406	-0.0475
23	0	Correlation	2.1633	1.9488	-0.2145
24	20	Biased	1.9189	1.9335	0.0146
26	50	Biased	2.2097	2.0033	-0.2064
27	30	Unbiased	2.2488	1.8922	-0.3566
28	30	Biased	2.0889	2.0882	-0.0007
29	30	Unbiased	2.0622	2.0825	0.0203
30	20	Biased	2.0403	2.2144	0.1741
31	30	Unbiased	1.9567	1.937	-0.0197
33	30	Biased	2.0585	2.0647	0.0062
34	50	Unbiased	1.9689	2.1578	0.1889
35	20	Unbiased	2.2131	2.2239	0.0108
41	30	Biased	2.1711	2.0391	-0.132

Test Statistics ((1/fsw) s)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.1633	2.1898	2.2158	0.024085	1.9276	2.041	2.2131	0.1318	-0.276	-0.1488	0.0364	0.13522
20	1.9102	2.0551	2.2131	0.11964	1.8714	2.051	2.2239	0.13961	-0.2482	-0.00417	0.1915	0.1313
30	1.8765	2.0289	2.2488	0.11919	1.8357	1.9757	2.0882	0.09067	-0.3566	-0.05321	0.0217	0.1177
50	1.8233	2.0717	2.3788	0.15608	1.8018	2.0308	2.3422	0.14683	-0.2064	-0.04092	0.1889	0.10455

Device Test: 20.168 FREQ|DETECTION/RT/4.5/4.5/0/0/4.5/1MHz//@T_INT_CLK_DET





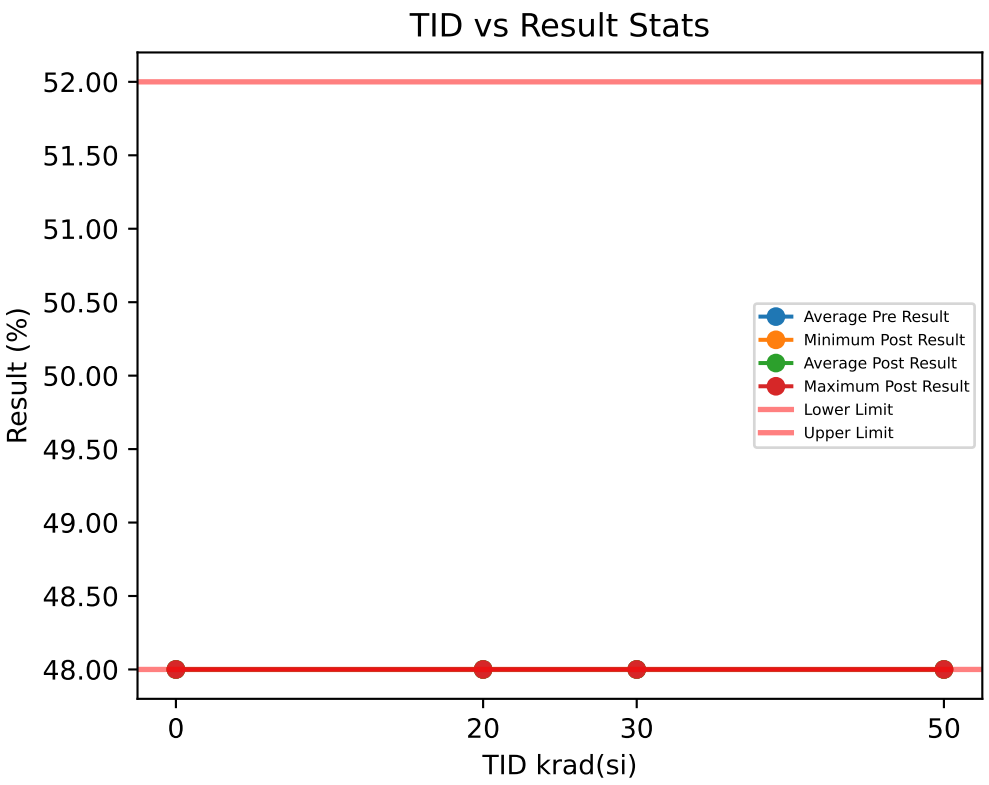
Test Results (Upper Limit = 5.0 ((1/fsw) s))

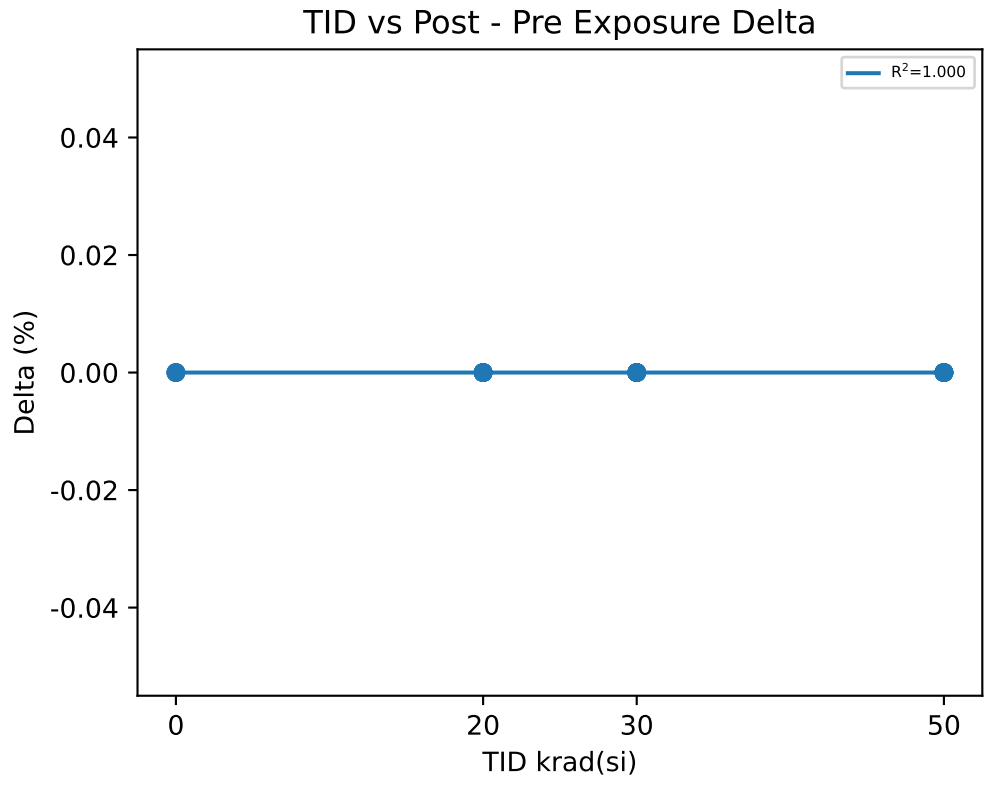
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	2.046	2.1609	0.1149
2	20	Unbiased	1.9162	2.2819	0.3657
3	50	Biased	2.1517	2.2416	0.0899
4	30	Unbiased	1.8732	2.0841	0.2109
5	50	Unbiased	2.2068	2.1188	-0.088
6	30	Biased	1.9243	2.1396	0.2153
7	50	Biased	2.1028	2.1832	0.0804
8	30	Unbiased	2.0368	2.0222	-0.0146
9	20	Unbiased	2.046	2.0938	0.0478
10	50	Biased	1.968	2.1306	0.1626
11	30	Biased	2.1836	2.2187	0.0351
12	0	Correlation	1.9604	2.1688	0.2084
13	0	Correlation	2.2364	2.2247	-0.0117
14	50	Unbiased	1.9664	2.0586	0.0922
15	20	Biased	2.143	2.1552	0.0122
16	20	Unbiased	1.9252	1.974	0.0488
17	20	Biased	2.1568	2.0174	-0.1394
18	20	Unbiased	2.2096	1.9709	-0.2387
19	20	Biased	2.0968	2.1944	0.0976
20	50	Unbiased	1.9736	2.0138	0.0402
21	0	Correlation	2.1574	2.0028	-0.1546
22	50	Unbiased	2.0118	2.026	0.0142
23	0	Correlation	2.3063	1.9608	-0.3455
24	20	Biased	2.0087	1.9528	-0.0559
26	50	Biased	2.029	2.0278	-0.0012
27	30	Unbiased	2.3211	2.0753	-0.2458
28	30	Biased	2.0229	2.2333	0.2104
29	30	Unbiased	2.2368	2.0862	-0.1506
30	20	Biased	2.0437	2.1298	0.0861
31	30	Unbiased	2.0848	2.0793	-0.0055
33	30	Biased	2.1316	2.109	-0.0226
34	50	Unbiased	2.0172	2.257	0.2398
35	20	Unbiased	2.0757	2.2261	0.1504
41	30	Biased	2.1489	2.0661	-0.0828

Test Statistics ((1/fsw) s)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.9604	2.1651	2.3063	0.14942	1.9608	2.0893	2.2247	0.12734	-0.3455	-0.07585	0.2084	0.23368
20	1.9162	2.0622	2.2096	0.095531	1.9528	2.0996	2.2819	0.11686	-0.2387	0.03746	0.3657	0.16452
30	1.8732	2.0964	2.3211	0.13757	2.0222	2.1114	2.2333	0.06741	-0.2458	0.01498	0.2153	0.15804
50	1.9664	2.0473	2.2068	0.081777	2.0138	2.1218	2.257	0.089249	-0.088	0.0745	0.2398	0.090831

Device Test: 20.17 PF|DCL_48/SYNC/4.5/4.5/0/0/4.5/100kHz//@DUTY_SYNC_EXT_DCL50





Test Results (Lower Limit = 48.0, Upper Limit = 52.0 (%))

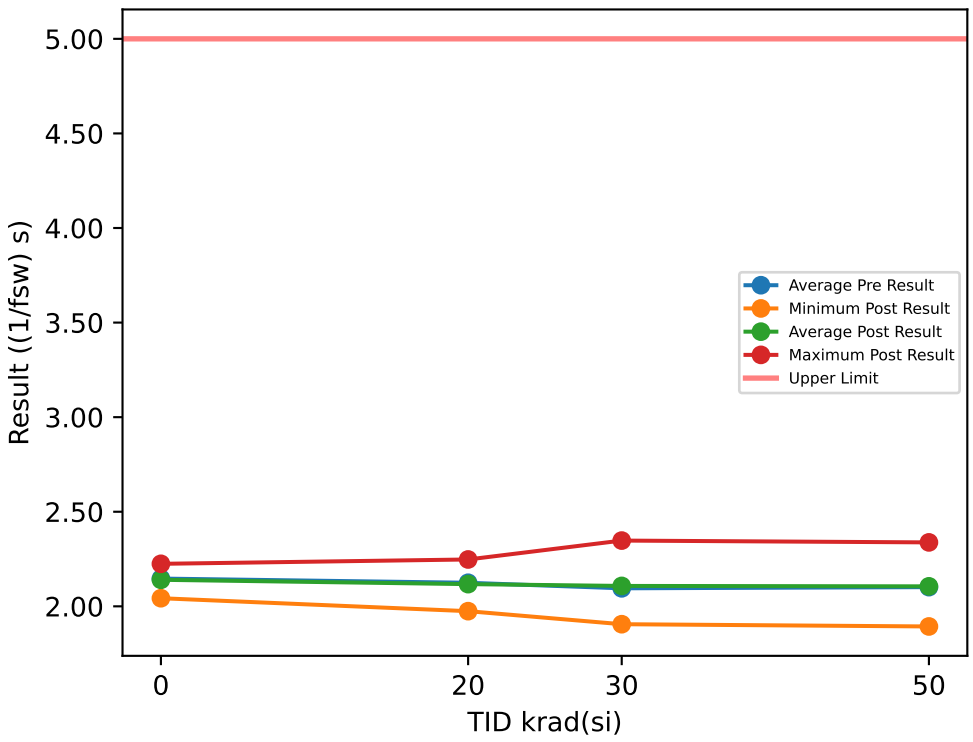
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	48	48	0
2	20	Unbiased	48	48	0
3	50	Biased	48	48	0
4	30	Unbiased	48	48	0
5	50	Unbiased	48	48	0
6	30	Biased	48	48	0
7	50	Biased	48	48	0
8	30	Unbiased	48	48	0
9	20	Unbiased	48	48	0
10	50	Biased	48	48	0
11	30	Biased	48	48	0
12	0	Correlation	48	48	0
13	0	Correlation	48	48	0
14	50	Unbiased	48	48	0
15	20	Biased	48	48	0
16	20	Unbiased	48	48	0
17	20	Biased	48	48	0
18	20	Unbiased	48	48	0
19	20	Biased	48	48	0
20	50	Unbiased	48	48	0
21	0	Correlation	48	48	0
22	50	Unbiased	48	48	0
23	0	Correlation	48	48	0
24	20	Biased	48	48	0
26	50	Biased	48	48	0
27	30	Unbiased	48	48	0
28	30	Biased	48	48	0
29	30	Unbiased	48	48	0
30	20	Biased	48	48	0
31	30	Unbiased	48	48	0
33	30	Biased	48	48	0
34	50	Unbiased	48	48	0
35	20	Unbiased	48	48	0
41	30	Biased	48	48	0

Test Statistics (%)

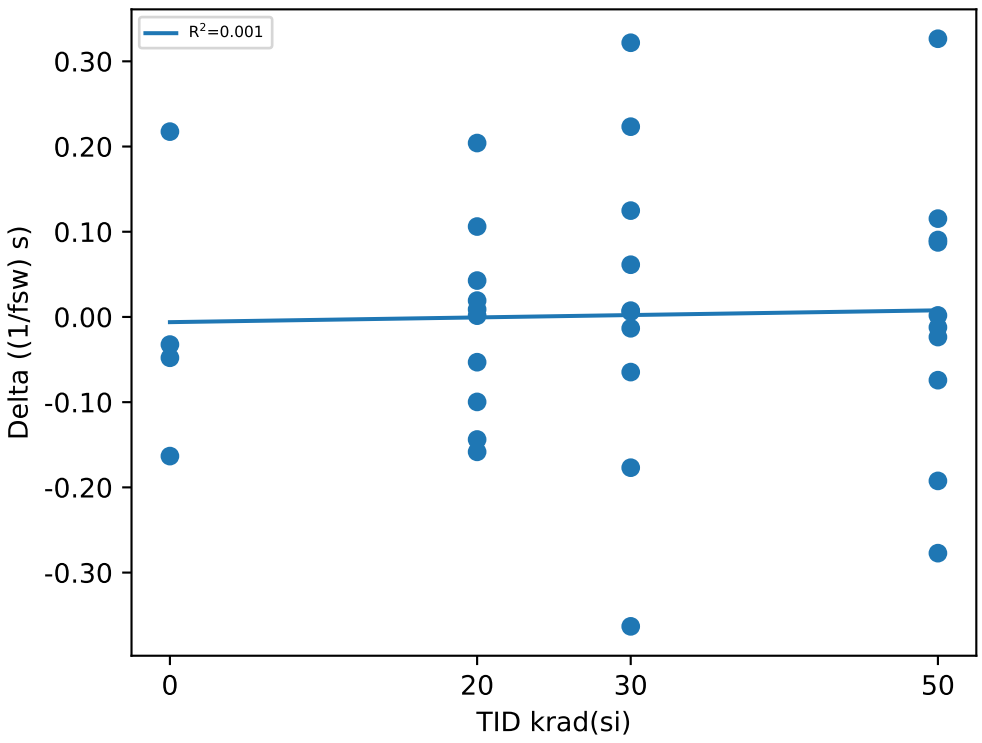
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	48	48	48	0	48	48	48	0	0	0	0	0
20	48	48	48	0	48	48	48	0	0	0	0	0
30	48	48	48	0	48	48	48	0	0	0	0	0
50	48	48	48	0	48	48	48	0	0	0	0	0

Device Test: 20.170 FREQ|DETECTION/RT/5/5/0/0/5/1MHz//@T_INT_CLK_DET

TID vs Result Stats



TID vs Post - Pre Exposure Delta



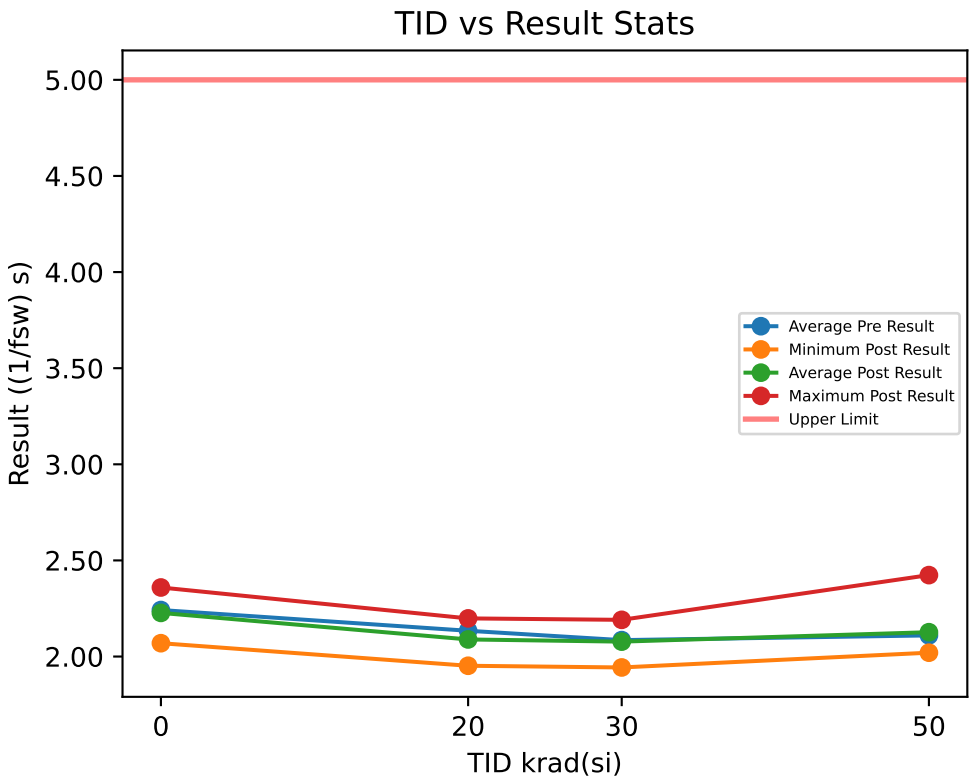
Test Results (Upper Limit = 5.0 ((1/fsw) s))

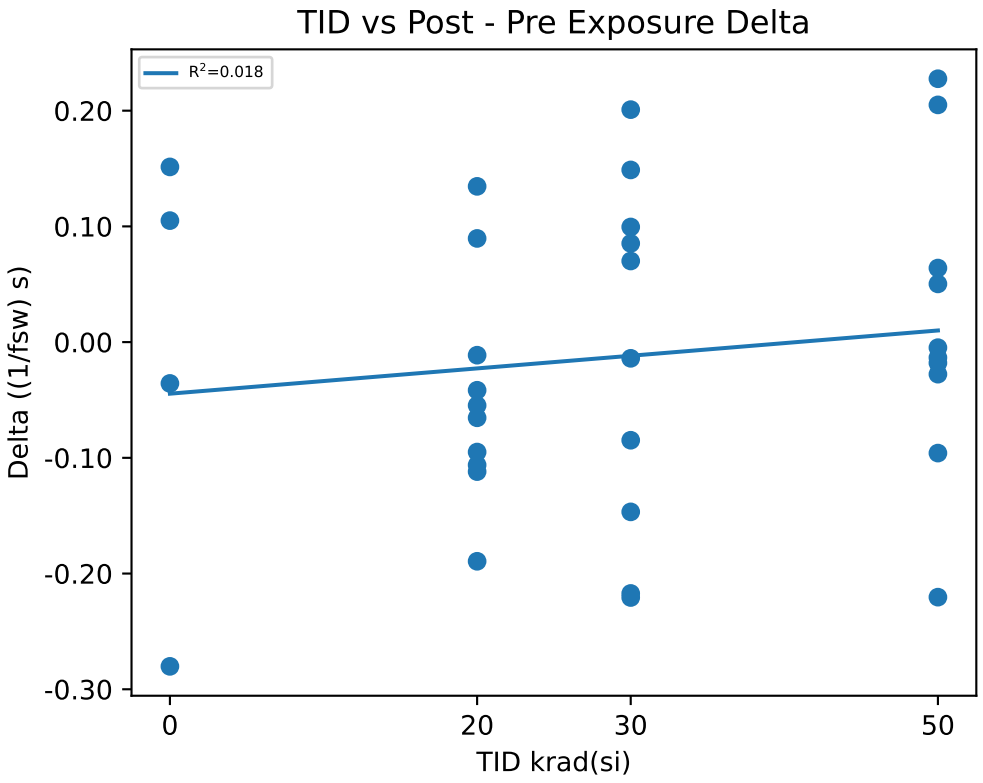
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	2.3689	2.0917	-0.2772
2	20	Unbiased	2.0436	2.2477	0.2041
3	50	Biased	2.2898	2.0974	-0.1924
4	30	Unbiased	2.0107	1.9974	-0.0133
5	50	Unbiased	2.2477	2.338	0.0903
6	30	Biased	2.0258	2.3476	0.3218
7	50	Biased	2.1129	2.1007	-0.0122
8	30	Unbiased	2.0348	2.0422	0.0074
9	20	Unbiased	2.1182	1.9744	-0.1438
10	50	Biased	2.0863	2.2017	0.1154
11	30	Biased	1.9793	2.0406	0.0613
12	0	Correlation	2.0072	2.2247	0.2175
13	0	Correlation	2.2502	2.2178	-0.0324
14	50	Unbiased	1.9172	1.8936	-0.0236
15	20	Biased	2.153	2.0533	-0.0997
16	20	Unbiased	2.0896	2.0985	0.0089
17	20	Biased	2.1576	1.9993	-0.1583
18	20	Unbiased	2.167	2.1685	0.0015
19	20	Biased	2.1872	2.1341	-0.0531
20	50	Unbiased	1.9989	2.0007	0.0018
21	0	Correlation	2.1234	2.0755	-0.0479
22	50	Unbiased	2.1527	2.0785	-0.0742
23	0	Correlation	2.2062	2.0429	-0.1633
24	20	Biased	1.9928	2.0989	0.1061
26	50	Biased	1.8986	1.9861	0.0875
27	30	Unbiased	2.3753	2.0122	-0.3631
28	30	Biased	1.9101	2.1334	0.2233
29	30	Unbiased	2.2479	2.1832	-0.0647
30	20	Biased	2.1116	2.1543	0.0427
31	30	Unbiased	2.0824	1.9055	-0.1769
33	30	Biased	2.2274	2.2336	0.0062
34	50	Unbiased	1.9417	2.2682	0.3265
35	20	Unbiased	2.2254	2.2446	0.0192
41	30	Biased	2.0584	2.1832	0.1248

Test Statistics ((1/fsw) s)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.0072	2.1467	2.2502	0.10686	2.0429	2.1402	2.2247	0.094543	-0.1633	-0.006525	0.2175	0.16036
20	1.9928	2.1246	2.2254	0.069234	1.9744	2.1174	2.2477	0.092264	-0.1583	-0.00724	0.2041	0.11213
30	1.9101	2.0952	2.3753	0.14301	1.9055	2.1079	2.3476	0.13184	-0.3631	0.01268	0.3218	0.194
50	1.8986	2.1015	2.3689	0.16415	1.8936	2.1057	2.338	0.13372	-0.2772	0.00419	0.3265	0.16853

Device Test: 20.172 FREQ|DETECTION/RT/12/12/0/0/5/1MHz//@T_INT_CLK_DET





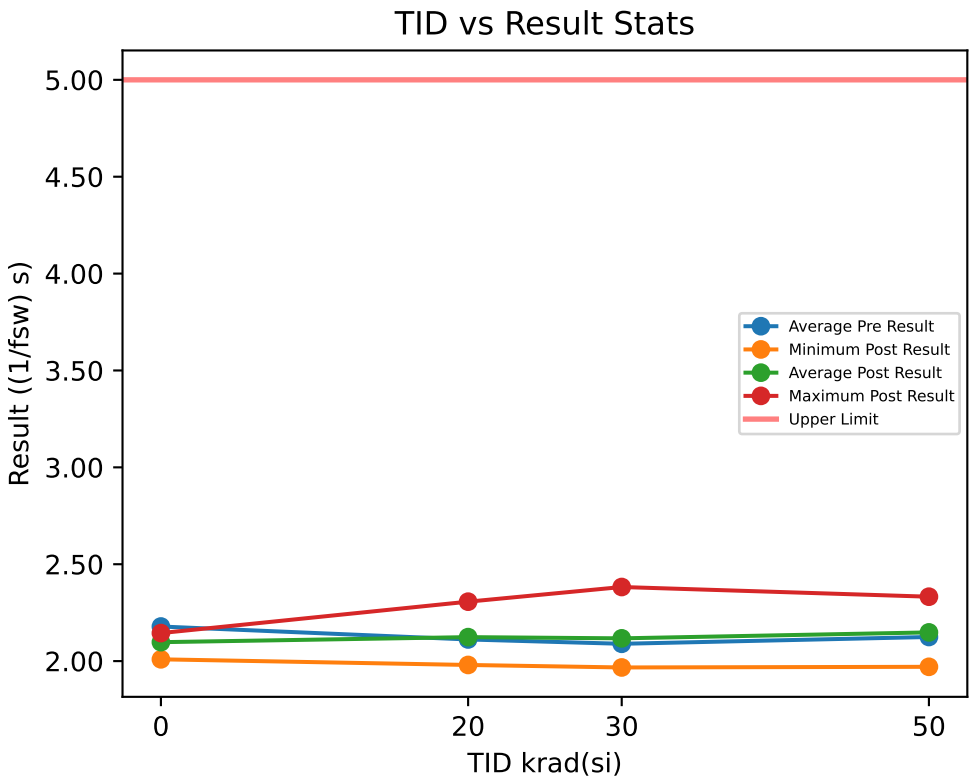
Test Results (Upper Limit = 5.0 ((1/fsw) s))

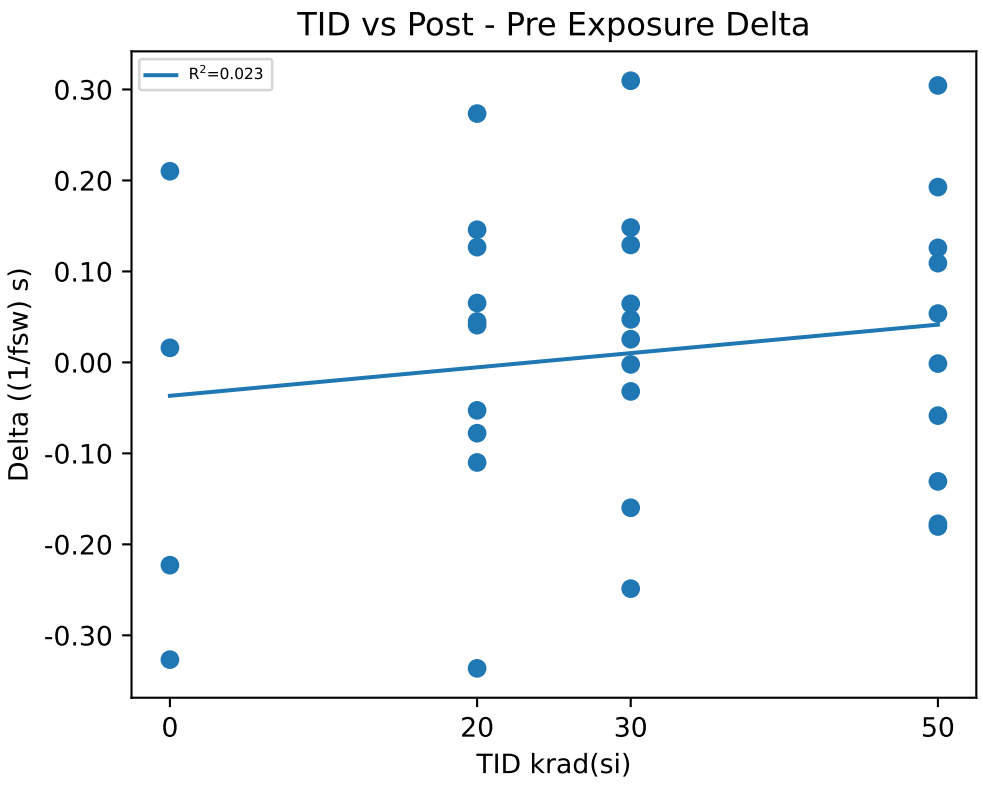
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	2.2813	2.0609	-0.2204
2	20	Unbiased	2.1298	2.0236	-0.1062
3	50	Biased	2.1674	2.154	-0.0134
4	30	Unbiased	2.028	1.9432	-0.0848
5	50	Unbiased	2.2186	2.4236	0.205
6	30	Biased	2.0647	2.15	0.0853
7	50	Biased	2.2276	2.1999	-0.0277
8	30	Unbiased	2.0039	2.1527	0.1488
9	20	Unbiased	2.174	2.1627	-0.0113
10	50	Biased	2.1293	2.1245	-0.0048
11	30	Biased	2.2264	2.0797	-0.1467
12	0	Correlation	2.2078	2.3592	0.1514
13	0	Correlation	2.2375	2.3425	0.105
14	50	Unbiased	2.1212	2.0253	-0.0959
15	20	Biased	2.0638	2.1984	0.1346
16	20	Unbiased	2.2033	2.0139	-0.1894
17	20	Biased	2.2159	2.104	-0.1119
18	20	Unbiased	2.0067	1.952	-0.0547
19	20	Biased	2.1764	2.1348	-0.0416
20	50	Unbiased	2.0525	2.0345	-0.018
21	0	Correlation	2.3496	2.0694	-0.2802
22	50	Unbiased	1.956	2.02	0.064
23	0	Correlation	2.1727	2.137	-0.0357
24	20	Biased	2.0126	2.1022	0.0896
26	50	Biased	1.9845	2.0348	0.0503
27	30	Unbiased	2.1657	1.945	-0.2207
28	30	Biased	1.988	2.1889	0.2009
29	30	Unbiased	2.0544	2.1539	0.0995
30	20	Biased	2.2179	2.1229	-0.095
31	30	Unbiased	2.1625	1.9453	-0.2172
33	30	Biased	2.1208	2.1909	0.0701
34	50	Unbiased	1.9609	2.1885	0.2276
35	20	Unbiased	2.1401	2.0747	-0.0654
41	30	Biased	2.0397	2.0257	-0.014

Test Statistics ((1/fsw) s)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.1727	2.2419	2.3496	0.076529	2.0694	2.227	2.3592	0.14578	-0.2802	-0.014875	0.1514	0.19395
20	2.0067	2.134	2.2179	0.080189	1.952	2.0889	2.1984	0.074488	-0.1894	-0.04513	0.1346	0.096381
30	1.988	2.0854	2.2264	0.079182	1.9432	2.0775	2.1909	0.10423	-0.2207	-0.00788	0.2009	0.1523
50	1.956	2.1099	2.2813	0.11727	2.02	2.1266	2.4236	0.12518	-0.2204	0.01667	0.2276	0.13197

Device Test: 20.174 FREQ|DETECTION/RT/14/14/0/0/5/1MHz//@T_INT_CLK_DET





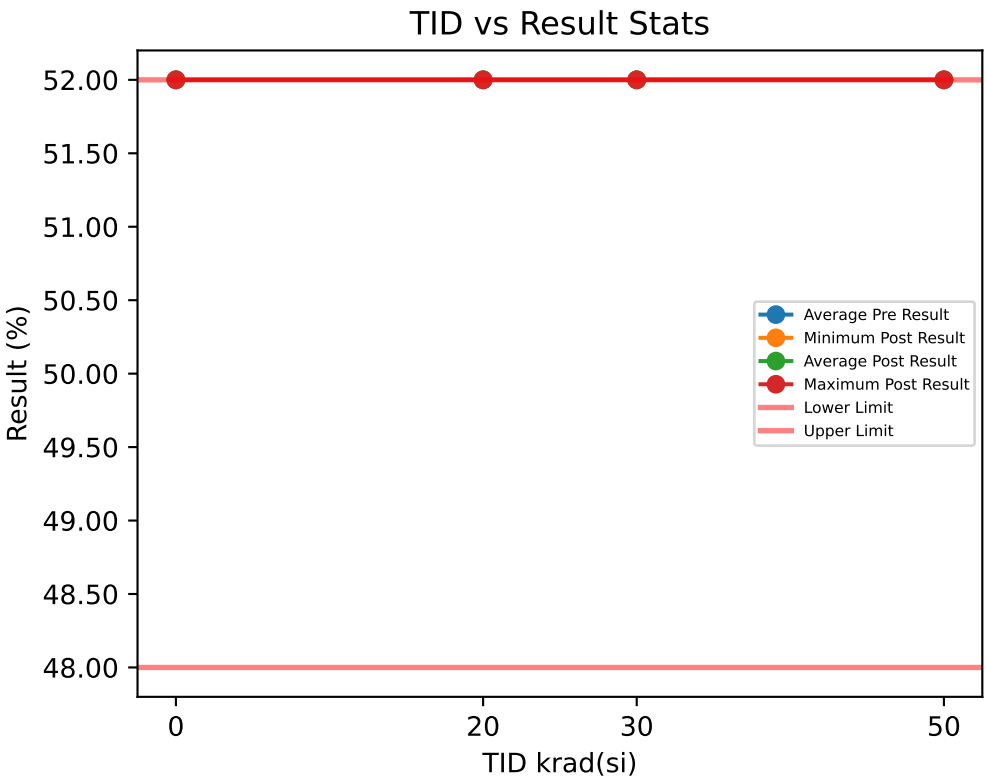
Test Results (Upper Limit = 5.0 ((1/fsw) s))

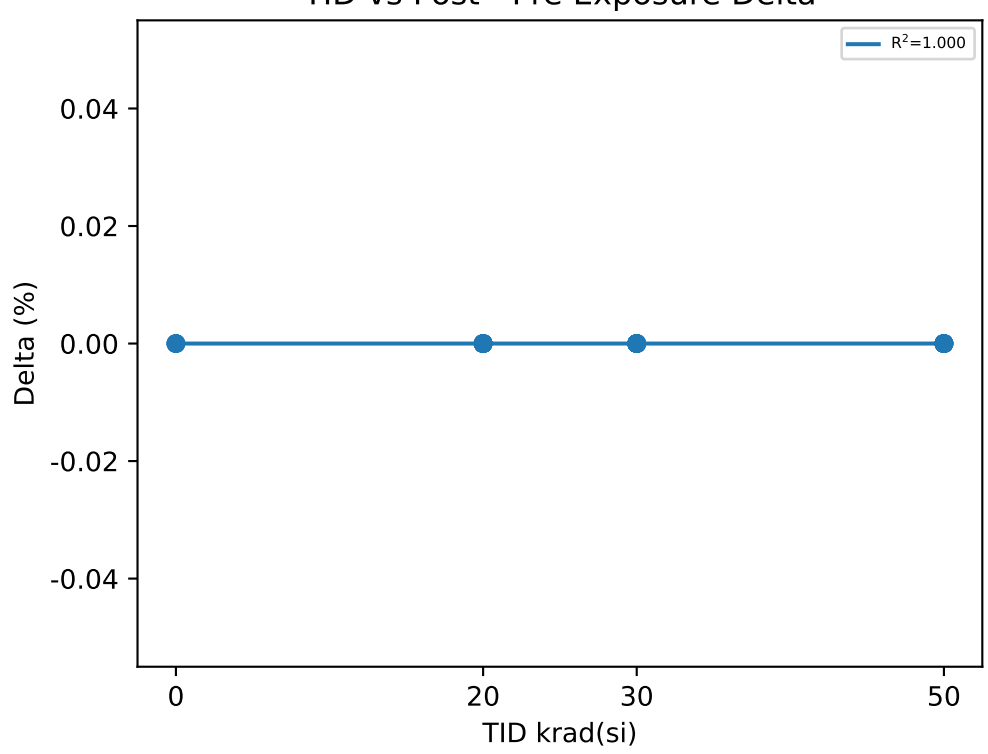
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	2.3583	2.1779	-0.1804
2	20	Unbiased	2.0881	2.1331	0.045
3	50	Biased	2.2944	2.2359	-0.0585
4	30	Unbiased	1.9248	1.9721	0.0473
5	50	Unbiased	2.2129	2.2116	-0.0013
6	30	Biased	2.0728	2.3824	0.3096
7	50	Biased	2.2233	2.3324	0.1091
8	30	Unbiased	2.0203	2.0181	-0.0022
9	20	Unbiased	2.3438	2.0075	-0.3363
10	50	Biased	1.8761	2.1805	0.3044
11	30	Biased	1.9651	2.0295	0.0644
12	0	Correlation	1.9265	2.1366	0.2101
13	0	Correlation	2.3232	2.1003	-0.2229
14	50	Unbiased	1.8728	2.0655	0.1927
15	20	Biased	2.0332	2.3067	0.2735
16	20	Unbiased	2.0414	2.1067	0.0653
17	20	Biased	2.0579	2.0988	0.0409
18	20	Unbiased	1.9833	2.11	0.1267
19	20	Biased	2.1655	2.0877	-0.0778
20	50	Unbiased	2.1479	1.9705	-0.1774
21	0	Correlation	2.3359	2.0092	-0.3267
22	50	Unbiased	1.9885	2.1144	0.1259
23	0	Correlation	2.1286	2.1446	0.016
24	20	Biased	2.0901	1.9801	-0.11
26	50	Biased	2.1848	2.054	-0.1308
27	30	Unbiased	2.2159	1.9672	-0.2487
28	30	Biased	2.0428	2.191	0.1482
29	30	Unbiased	2.0928	2.2219	0.1291
30	20	Biased	2.1474	2.2932	0.1458
31	30	Unbiased	2.0567	2.0248	-0.0319
33	30	Biased	2.4373	2.2775	-0.1598
34	50	Unbiased	2.0852	2.1389	0.0537
35	20	Unbiased	2.1661	2.1134	-0.0527
41	30	Biased	2.0647	2.0902	0.0255

Test Statistics ((1/fsw) s)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.9265	2.1785	2.3359	0.19297	2.0092	2.0977	2.1446	0.062053	-0.3267	-0.080875	0.2101	0.24128
20	1.9833	2.1117	2.3438	0.10138	1.9801	2.1237	2.3067	0.10484	-0.3363	0.01204	0.2735	0.16755
30	1.9248	2.0893	2.4373	0.14472	1.9672	2.1175	2.3824	0.1425	-0.2487	0.02815	0.3096	0.15706
50	1.8728	2.1244	2.3583	0.16679	1.9705	2.1482	2.3324	0.10333	-0.1804	0.02374	0.3044	0.16308

Device Test: 20.18 PF|DCL_52/SYNC/4.5/4.5/0/0/4.5/100kHz//@DUTY_SYNC_EXT_DCL50





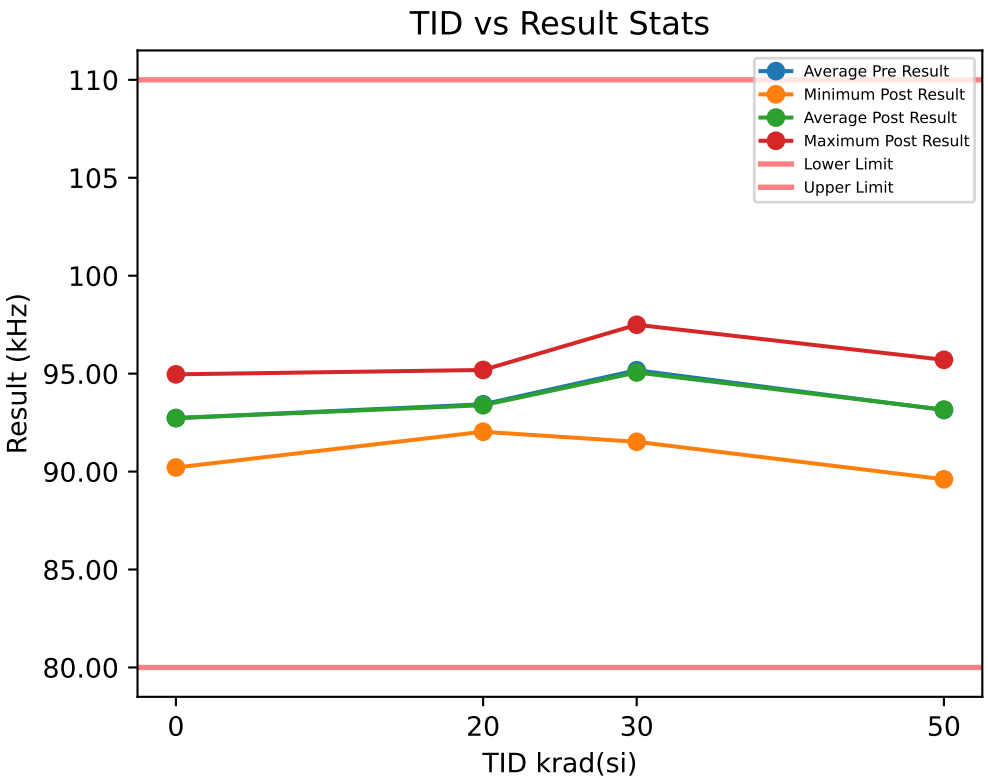
Test Results (Lower Limit = 48.0, Upper Limit = 52.0 (%))

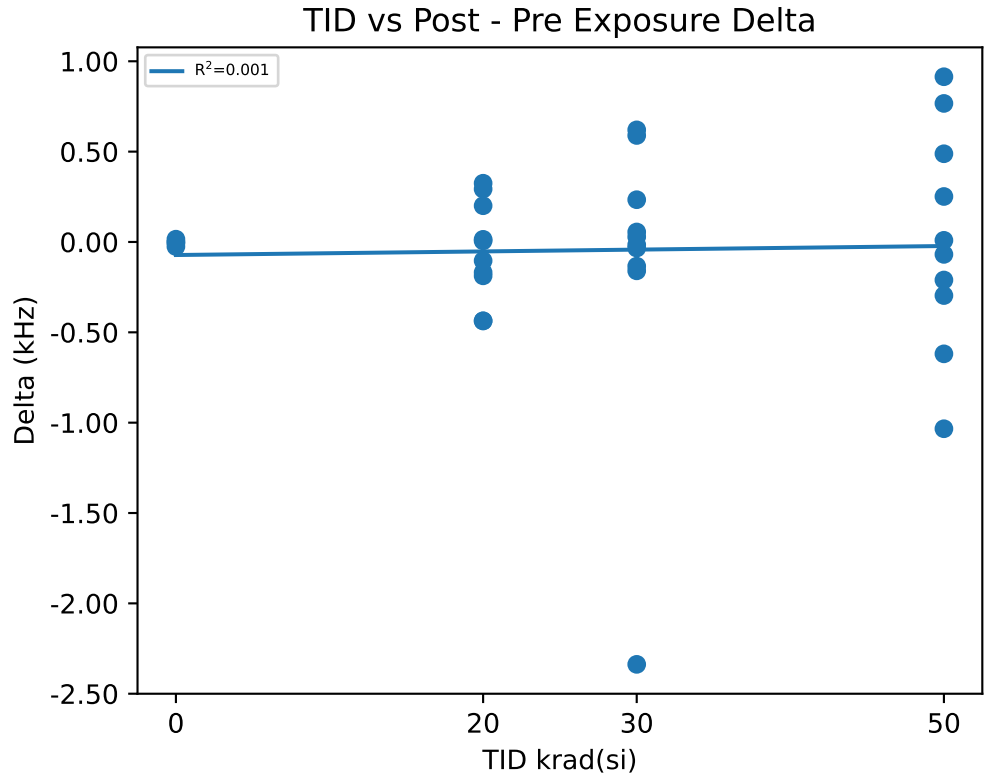
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	52	52	0
2	20	Unbiased	52	52	0
3	50	Biased	52	52	0
4	30	Unbiased	52	52	0
5	50	Unbiased	52	52	0
6	30	Biased	52	52	0
7	50	Biased	52	52	0
8	30	Unbiased	52	52	0
9	20	Unbiased	52	52	0
10	50	Biased	52	52	0
11	30	Biased	52	52	0
12	0	Correlation	52	52	0
13	0	Correlation	52	52	0
14	50	Unbiased	52	52	0
15	20	Biased	52	52	0
16	20	Unbiased	52	52	0
17	20	Biased	52	52	0
18	20	Unbiased	52	52	0
19	20	Biased	52	52	0
20	50	Unbiased	52	52	0
21	0	Correlation	52	52	0
22	50	Unbiased	52	52	0
23	0	Correlation	52	52	0
24	20	Biased	52	52	0
26	50	Biased	52	52	0
27	30	Unbiased	52	52	0
28	30	Biased	52	52	0
29	30	Unbiased	52	52	0
30	20	Biased	52	52	0
31	30	Unbiased	52	52	0
33	30	Biased	52	52	0
34	50	Unbiased	52	52	0
35	20	Unbiased	52	52	0
41	30	Biased	52	52	0

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	52	52	52	0	52	52	52	0	0	0	0	0
20	52	52	52	0	52	52	52	0	0	0	0	0
30	52	52	52	0	52	52	52	0	0	0	0	0
50	52	52	52	0	52	52	52	0	0	0	0	0

Device Test: 20.19 LEVEL|FREQ/RT/5/5/0/0/5/100kHz//@FSW_EXT_RT_A





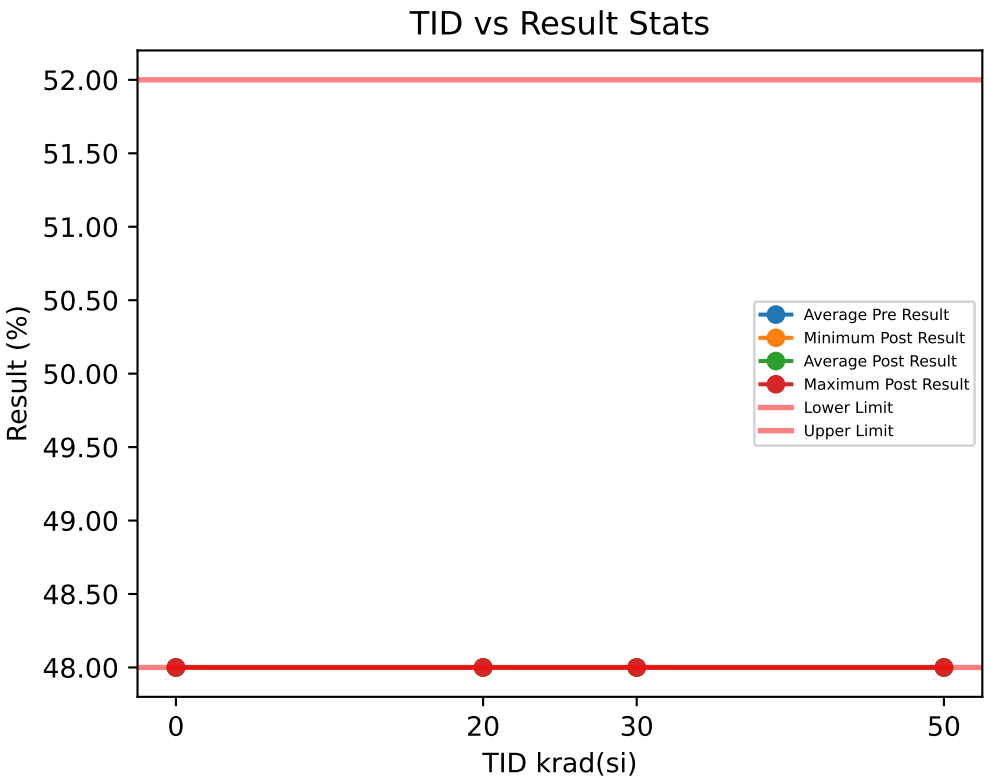
Test Results (Lower Limit = 80.0, Upper Limit = 110.0 (kHz))

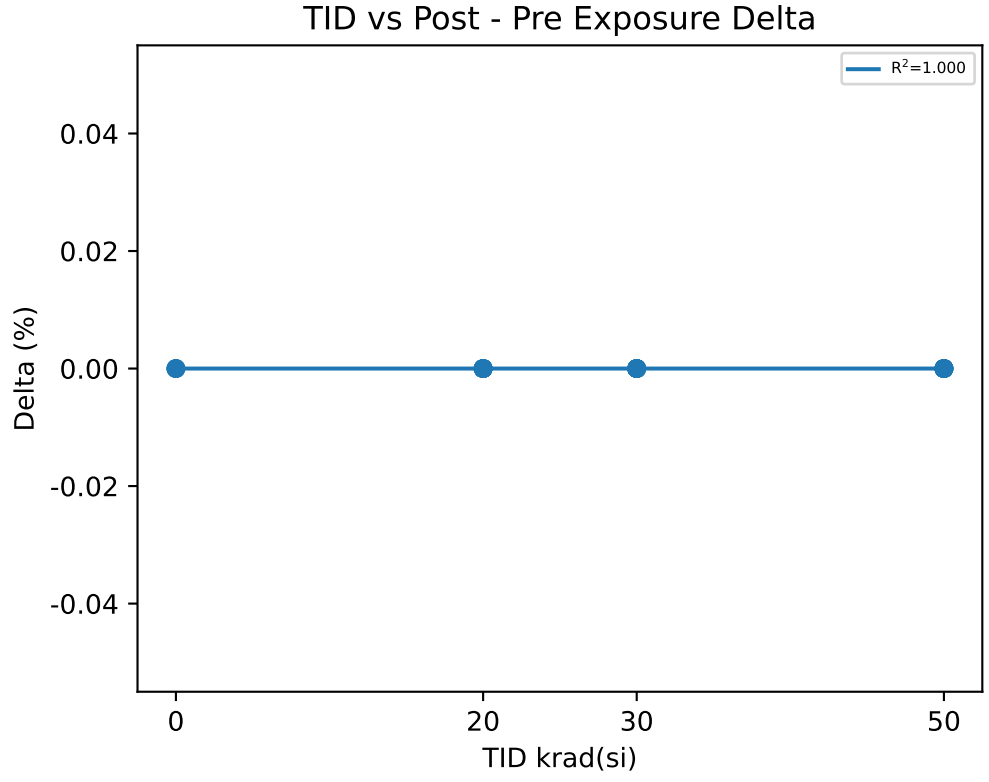
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	91.658	91.362	-0.2965
2	20	Unbiased	93.716	93.548	-0.1685
3	50	Biased	94.185	94.673	0.4882
4	30	Unbiased	95.523	95.389	-0.134
5	50	Unbiased	90.64	89.606	-1.0336
6	30	Biased	93.374	93.963	0.5894
7	50	Biased	93.947	93.736	-0.2105
8	30	Unbiased	94.677	94.732	0.0553
9	20	Unbiased	92.137	92.033	-0.1037
10	50	Biased	94.986	95.238	0.2517
11	30	Biased	95.658	96.279	0.6204
12	0	Correlation	90.21	90.209	-0.0012
13	0	Correlation	92.854	92.869	0.0154
14	50	Unbiased	95.775	95.707	-0.0687
15	20	Biased	93.153	93.446	0.2929
16	20	Unbiased	92.553	92.878	0.3251
17	20	Biased	95.625	95.188	-0.437
18	20	Unbiased	93.825	93.388	-0.4364
19	20	Biased	93.322	93.134	-0.1874
20	50	Unbiased	93.032	92.412	-0.6191
21	0	Correlation	92.879	92.875	-0.0039
22	50	Unbiased	92.594	92.603	0.0091
23	0	Correlation	94.989	94.964	-0.0252
24	20	Biased	93.609	93.615	0.0061
26	50	Biased	93.431	94.198	0.7667
27	30	Unbiased	92.713	92.679	-0.0336
28	30	Biased	97.467	97.496	0.0283
29	30	Unbiased	97.545	97.386	-0.1597
30	20	Biased	92.872	93.073	0.2006
31	30	Unbiased	96.623	96.607	-0.0155
33	30	Biased	94.315	94.549	0.2339
34	50	Unbiased	91.175	92.089	0.9144
35	20	Unbiased	93.548	93.563	0.0146
41	30	Biased	93.858	91.521	-2.3375

Test Statistics (kHz)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	90.21	92.733	94.989	1.9572	90.209	92.729	94.964	1.9483	-0.0252	-0.003725	0.0154	0.016667
20	92.137	93.436	95.625	0.93952	92.033	93.387	95.188	0.78966	-0.437	-0.04937	0.3251	0.27147
30	92.713	95.175	97.545	1.6784	91.521	95.06	97.496	1.9747	-2.3375	-0.1153	0.6204	0.82776
50	90.64	93.142	95.775	1.6599	89.606	93.163	95.707	1.8968	-1.0336	0.02017	0.9144	0.60647

Device Test: 20.21 PF|DCL_48/SYNC/5/5/0/0/5/100kHz//@DUTY_SYNC_EXT_DCL50





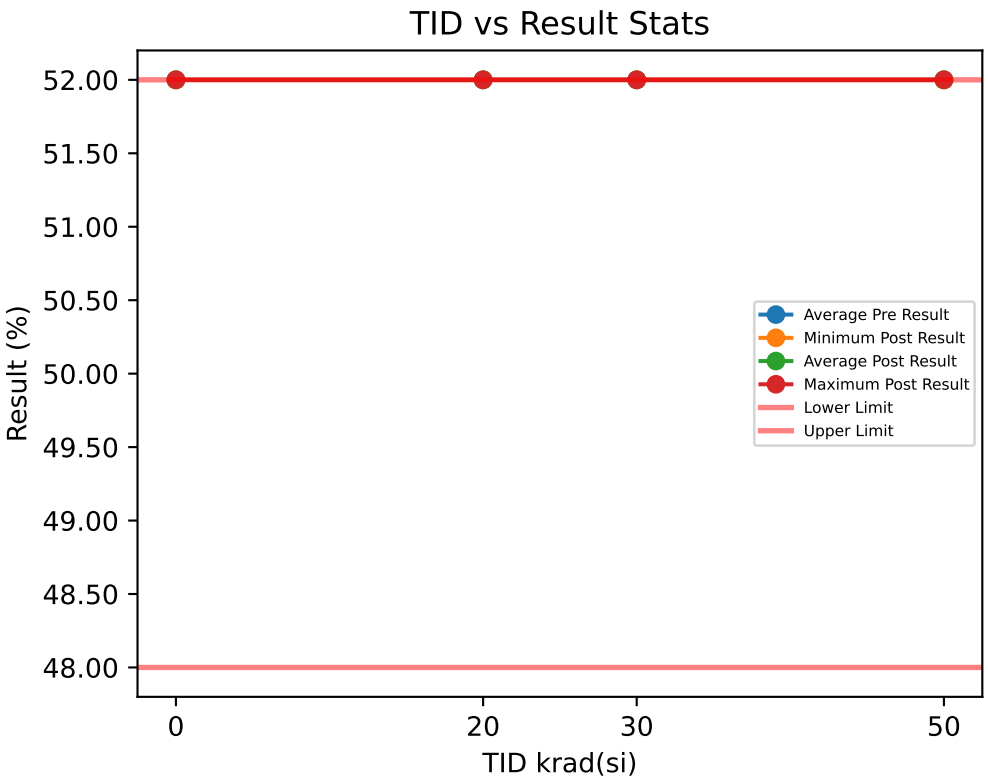
Test Results (Lower Limit = 48.0, Upper Limit = 52.0 (%))

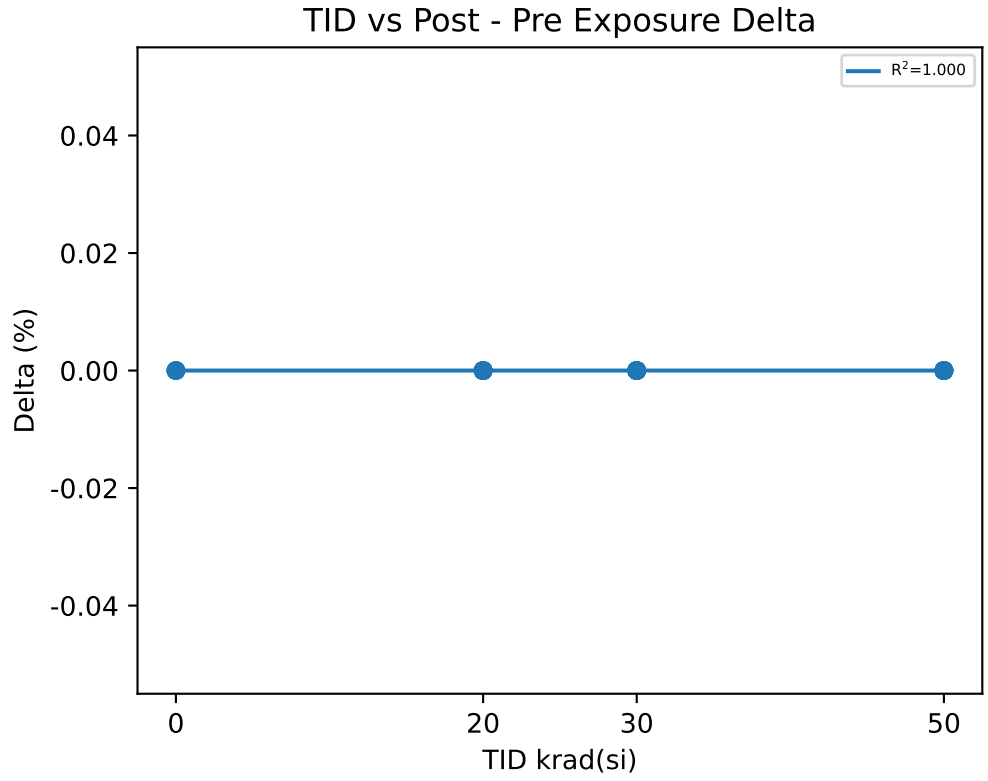
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	48	48	0
2	20	Unbiased	48	48	0
3	50	Biased	48	48	0
4	30	Unbiased	48	48	0
5	50	Unbiased	48	48	0
6	30	Biased	48	48	0
7	50	Biased	48	48	0
8	30	Unbiased	48	48	0
9	20	Unbiased	48	48	0
10	50	Biased	48	48	0
11	30	Biased	48	48	0
12	0	Correlation	48	48	0
13	0	Correlation	48	48	0
14	50	Unbiased	48	48	0
15	20	Biased	48	48	0
16	20	Unbiased	48	48	0
17	20	Biased	48	48	0
18	20	Unbiased	48	48	0
19	20	Biased	48	48	0
20	50	Unbiased	48	48	0
21	0	Correlation	48	48	0
22	50	Unbiased	48	48	0
23	0	Correlation	48	48	0
24	20	Biased	48	48	0
26	50	Biased	48	48	0
27	30	Unbiased	48	48	0
28	30	Biased	48	48	0
29	30	Unbiased	48	48	0
30	20	Biased	48	48	0
31	30	Unbiased	48	48	0
33	30	Biased	48	48	0
34	50	Unbiased	48	48	0
35	20	Unbiased	48	48	0
41	30	Biased	48	48	0

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	48	48	48	0	48	48	48	0	0	0	0	0
20	48	48	48	0	48	48	48	0	0	0	0	0
30	48	48	48	0	48	48	48	0	0	0	0	0
50	48	48	48	0	48	48	48	0	0	0	0	0

Device Test: 20.22 PF|DCL_52/SYNC/5/5/0/0/5/100kHz//@DUTY_SYNC_EXT_DCL50





Test Results (Lower Limit = 48.0, Upper Limit = 52.0 (%))

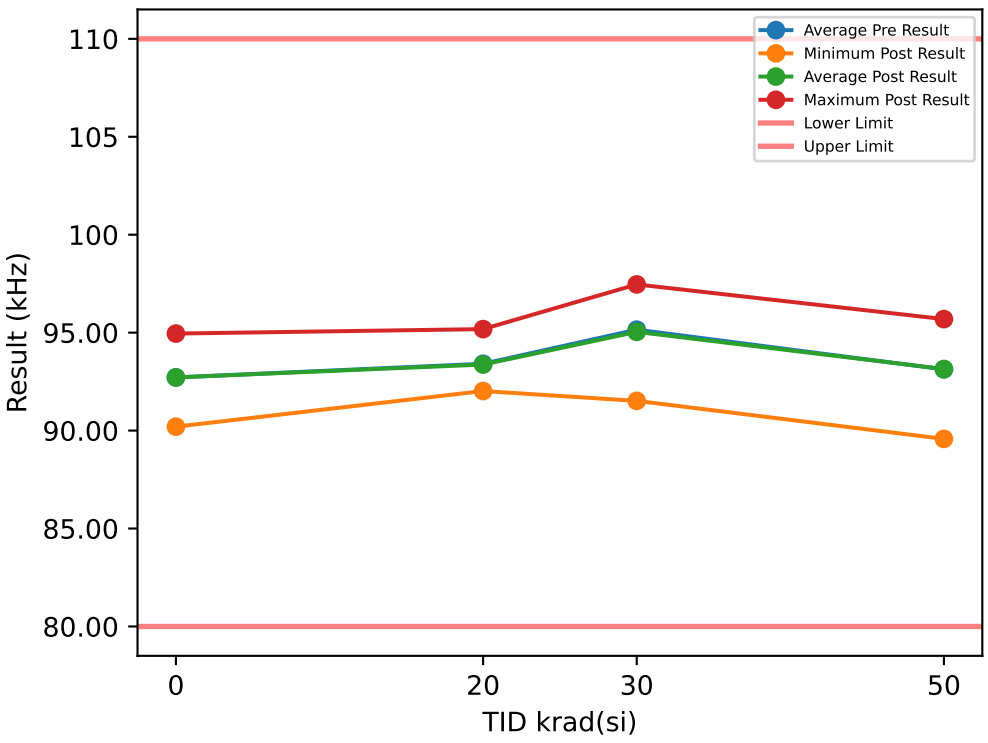
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	52	52	0
2	20	Unbiased	52	52	0
3	50	Biased	52	52	0
4	30	Unbiased	52	52	0
5	50	Unbiased	52	52	0
6	30	Biased	52	52	0
7	50	Biased	52	52	0
8	30	Unbiased	52	52	0
9	20	Unbiased	52	52	0
10	50	Biased	52	52	0
11	30	Biased	52	52	0
12	0	Correlation	52	52	0
13	0	Correlation	52	52	0
14	50	Unbiased	52	52	0
15	20	Biased	52	52	0
16	20	Unbiased	52	52	0
17	20	Biased	52	52	0
18	20	Unbiased	52	52	0
19	20	Biased	52	52	0
20	50	Unbiased	52	52	0
21	0	Correlation	52	52	0
22	50	Unbiased	52	52	0
23	0	Correlation	52	52	0
24	20	Biased	52	52	0
26	50	Biased	52	52	0
27	30	Unbiased	52	52	0
28	30	Biased	52	52	0
29	30	Unbiased	52	52	0
30	20	Biased	52	52	0
31	30	Unbiased	52	52	0
33	30	Biased	52	52	0
34	50	Unbiased	52	52	0
35	20	Unbiased	52	52	0
41	30	Biased	52	52	0

Test Statistics (%)

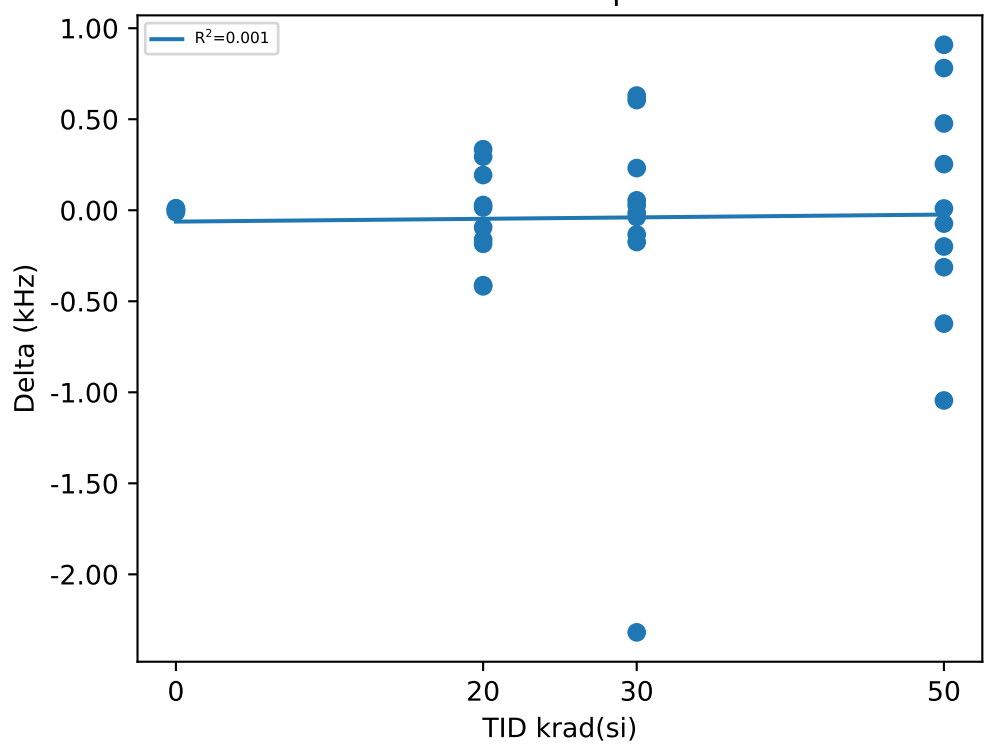
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	52	52	52	0	52	52	52	0	0	0	0	0
20	52	52	52	0	52	52	52	0	0	0	0	0
30	52	52	52	0	52	52	52	0	0	0	0	0
50	52	52	52	0	52	52	52	0	0	0	0	0

Device Test: 20.23 LEVEL|FREQ/RT/12/12/0/0/5/100kHz//@FSW_EXT_RT_A

TID vs Result Stats



TID vs Post - Pre Exposure Delta



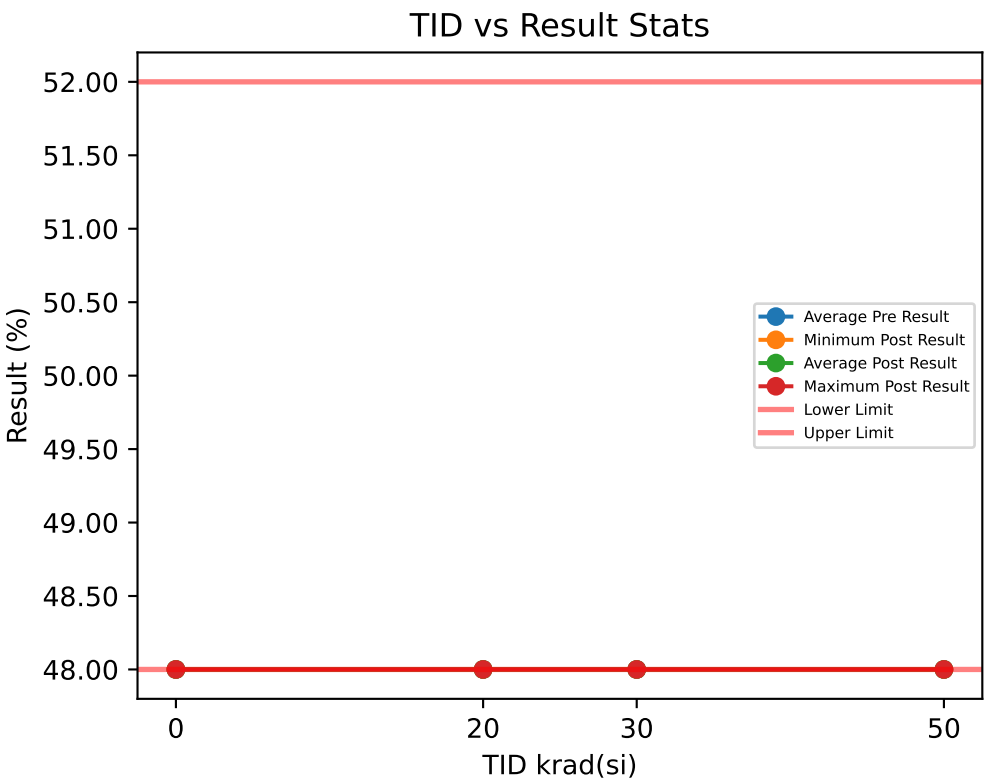
Test Results (Lower Limit = 80.0, Upper Limit = 110.0 (kHz))

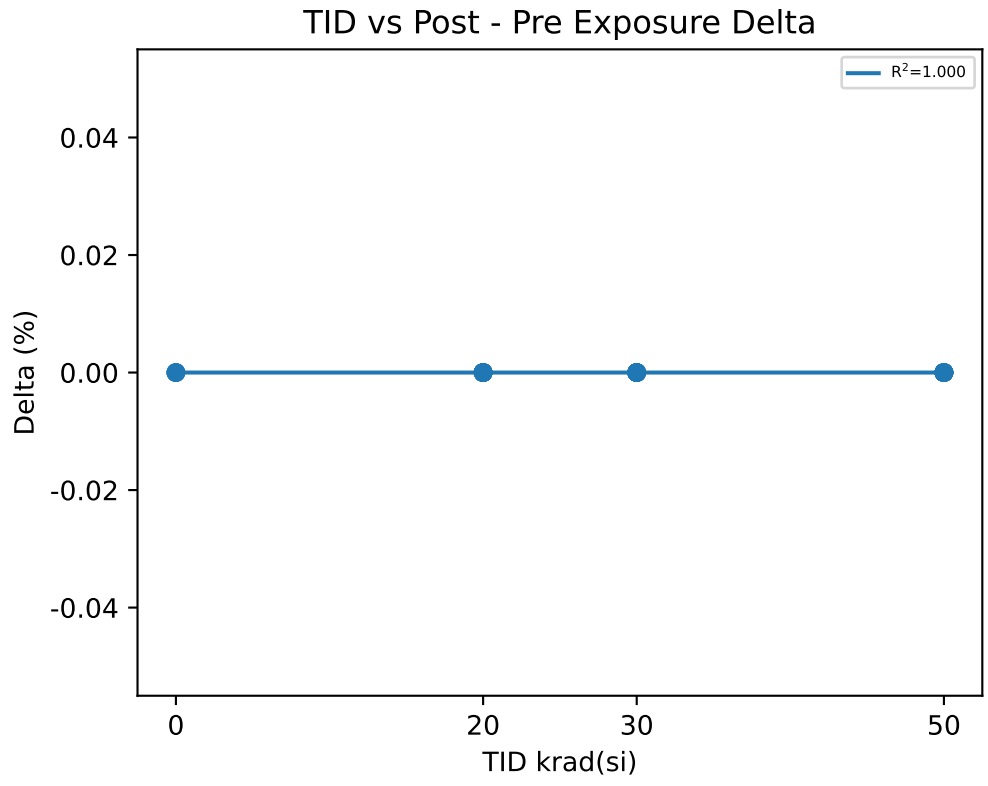
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	91.644	91.331	-0.3128
2	20	Unbiased	93.7	93.539	-0.1608
3	50	Biased	94.184	94.66	0.4767
4	30	Unbiased	95.513	95.38	-0.133
5	50	Unbiased	90.621	89.576	-1.0449
6	30	Biased	93.341	93.947	0.6051
7	50	Biased	93.911	93.712	-0.1992
8	30	Unbiased	94.654	94.709	0.0545
9	20	Unbiased	92.113	92.019	-0.094
10	50	Biased	94.973	95.227	0.2535
11	30	Biased	95.636	96.266	0.63
12	0	Correlation	90.187	90.199	0.0113
13	0	Correlation	92.836	92.836	-0.0002
14	50	Unbiased	95.765	95.692	-0.0732
15	20	Biased	93.136	93.431	0.2945
16	20	Unbiased	92.538	92.874	0.3353
17	20	Biased	95.592	95.18	-0.4115
18	20	Unbiased	93.795	93.377	-0.4179
19	20	Biased	93.295	93.11	-0.1845
20	50	Unbiased	93.015	92.392	-0.6227
21	0	Correlation	92.866	92.87	0.0034
22	50	Unbiased	92.573	92.582	0.0097
23	0	Correlation	94.963	94.953	-0.0103
24	20	Biased	93.578	93.593	0.0147
26	50	Biased	93.415	94.197	0.7811
27	30	Unbiased	92.692	92.655	-0.037
28	30	Biased	97.434	97.462	0.0274
29	30	Unbiased	97.528	97.354	-0.1744
30	20	Biased	92.849	93.043	0.1935
31	30	Unbiased	96.596	96.582	-0.0143
33	30	Biased	94.292	94.524	0.2317
34	50	Unbiased	91.159	92.068	0.9092
35	20	Unbiased	93.518	93.547	0.0289
41	30	Biased	93.836	91.517	-2.3187

Test Statistics (kHz)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	90.187	92.713	94.963	1.9563	90.199	92.714	94.953	1.9476	-0.0103	0.00105	0.0113	0.0089623
20	92.113	93.411	95.592	0.93554	92.019	93.371	95.18	0.7914	-0.4179	-0.04018	0.3353	0.26546
30	92.692	95.152	97.528	1.6784	91.517	95.04	97.462	1.9687	-2.3187	-0.11287	0.63	0.82456
50	90.621	93.126	95.765	1.6618	89.576	93.144	95.692	1.9035	-1.0449	0.01774	0.9092	0.60989

Device Test: 20.25 PF|DCL_48/SYNC/12/12/0/0/5/100kHz//@DUTY_SYNC_EXT_DCL50





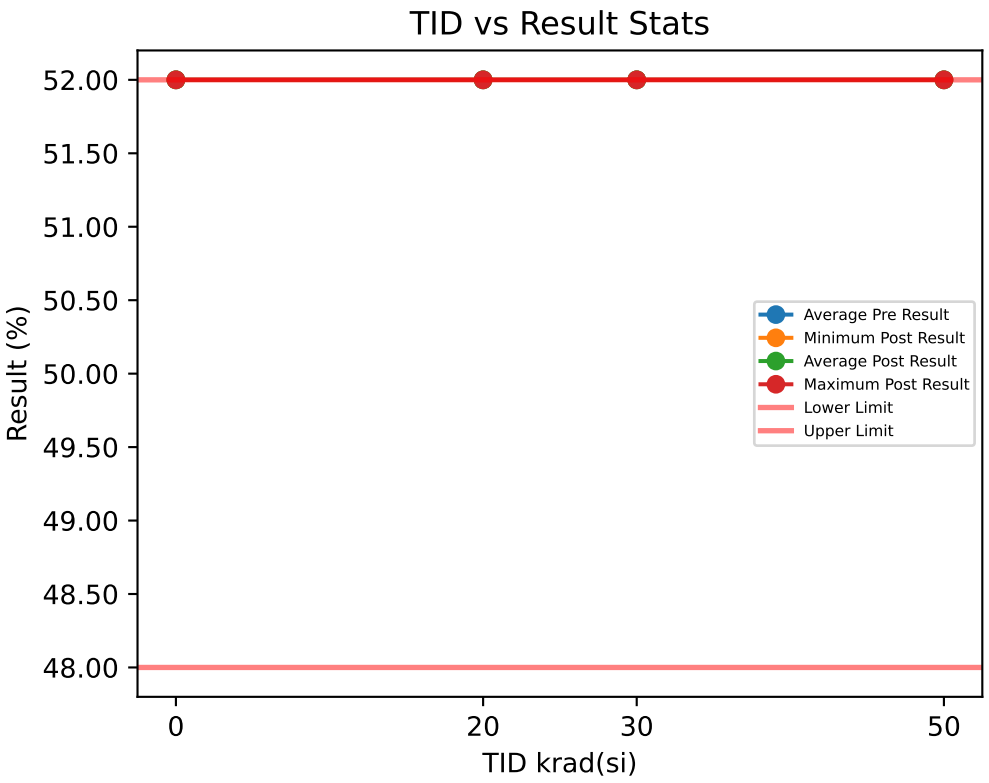
Test Results (Lower Limit = 48.0, Upper Limit = 52.0 (%))

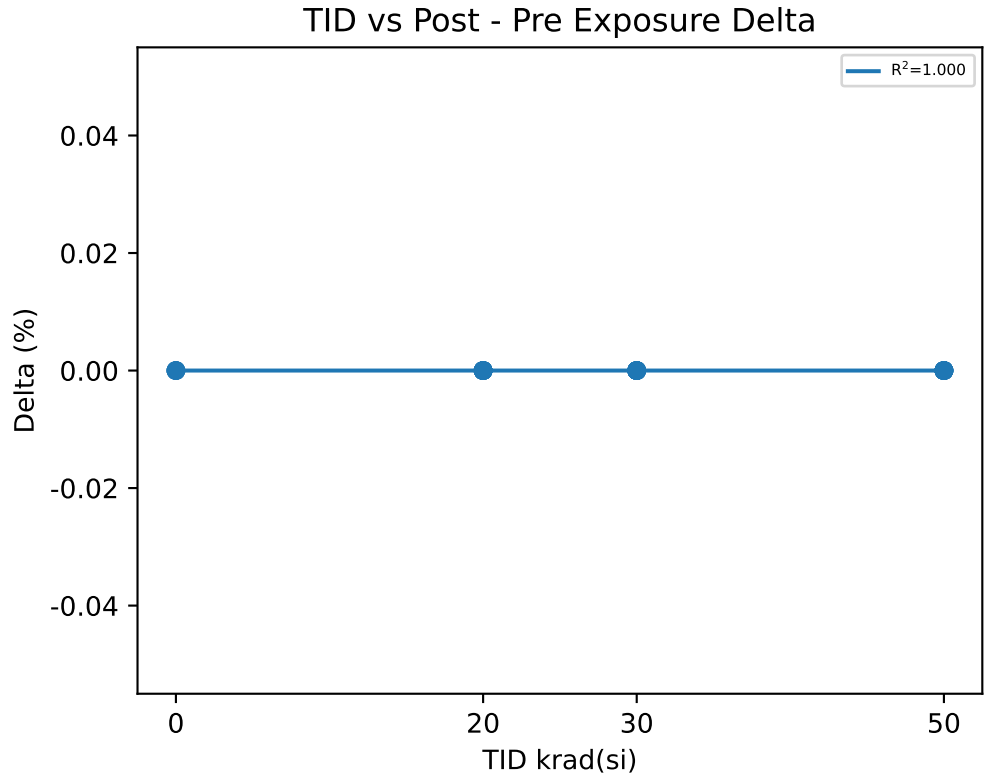
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	48	48	0
2	20	Unbiased	48	48	0
3	50	Biased	48	48	0
4	30	Unbiased	48	48	0
5	50	Unbiased	48	48	0
6	30	Biased	48	48	0
7	50	Biased	48	48	0
8	30	Unbiased	48	48	0
9	20	Unbiased	48	48	0
10	50	Biased	48	48	0
11	30	Biased	48	48	0
12	0	Correlation	48	48	0
13	0	Correlation	48	48	0
14	50	Unbiased	48	48	0
15	20	Biased	48	48	0
16	20	Unbiased	48	48	0
17	20	Biased	48	48	0
18	20	Unbiased	48	48	0
19	20	Biased	48	48	0
20	50	Unbiased	48	48	0
21	0	Correlation	48	48	0
22	50	Unbiased	48	48	0
23	0	Correlation	48	48	0
24	20	Biased	48	48	0
26	50	Biased	48	48	0
27	30	Unbiased	48	48	0
28	30	Biased	48	48	0
29	30	Unbiased	48	48	0
30	20	Biased	48	48	0
31	30	Unbiased	48	48	0
33	30	Biased	48	48	0
34	50	Unbiased	48	48	0
35	20	Unbiased	48	48	0
41	30	Biased	48	48	0

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	48	48	48	0	48	48	48	0	0	0	0	0
20	48	48	48	0	48	48	48	0	0	0	0	0
30	48	48	48	0	48	48	48	0	0	0	0	0
50	48	48	48	0	48	48	48	0	0	0	0	0

Device Test: 20.26 PF|DCL_52/SYNC/12/12/0/0/5/100kHz//@DUTY_SYNC_EXT_DCL50





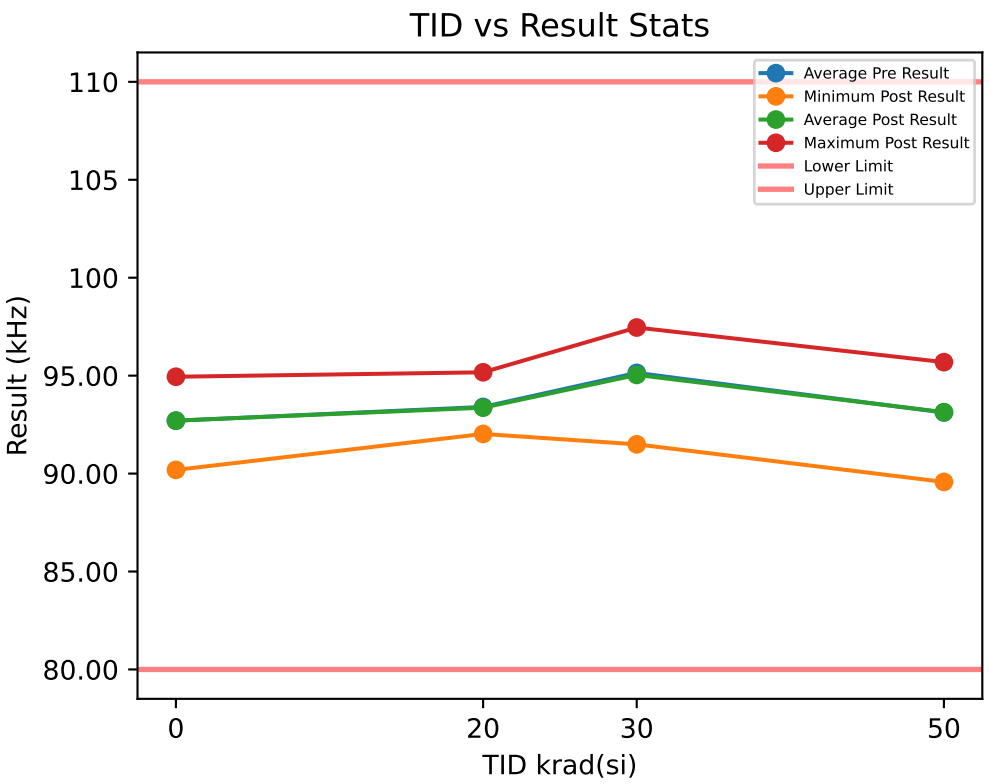
Test Results (Lower Limit = 48.0, Upper Limit = 52.0 (%))

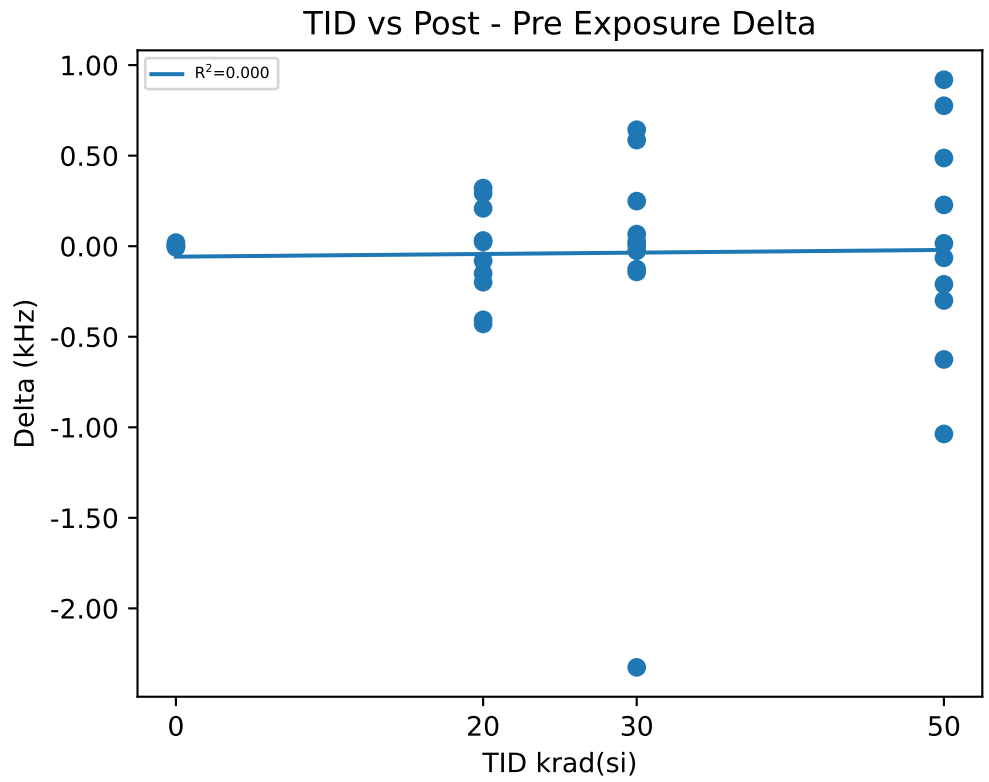
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	52	52	0
2	20	Unbiased	52	52	0
3	50	Biased	52	52	0
4	30	Unbiased	52	52	0
5	50	Unbiased	52	52	0
6	30	Biased	52	52	0
7	50	Biased	52	52	0
8	30	Unbiased	52	52	0
9	20	Unbiased	52	52	0
10	50	Biased	52	52	0
11	30	Biased	52	52	0
12	0	Correlation	52	52	0
13	0	Correlation	52	52	0
14	50	Unbiased	52	52	0
15	20	Biased	52	52	0
16	20	Unbiased	52	52	0
17	20	Biased	52	52	0
18	20	Unbiased	52	52	0
19	20	Biased	52	52	0
20	50	Unbiased	52	52	0
21	0	Correlation	52	52	0
22	50	Unbiased	52	52	0
23	0	Correlation	52	52	0
24	20	Biased	52	52	0
26	50	Biased	52	52	0
27	30	Unbiased	52	52	0
28	30	Biased	52	52	0
29	30	Unbiased	52	52	0
30	20	Biased	52	52	0
31	30	Unbiased	52	52	0
33	30	Biased	52	52	0
34	50	Unbiased	52	52	0
35	20	Unbiased	52	52	0
41	30	Biased	52	52	0

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	52	52	52	0	52	52	52	0	0	0	0	0
20	52	52	52	0	52	52	52	0	0	0	0	0
30	52	52	52	0	52	52	52	0	0	0	0	0
50	52	52	52	0	52	52	52	0	0	0	0	0

Device Test: 20.27 LEVEL|FREQ/RT/14/14/0/0/5/100kHz//@FSW_EXT_RT_A





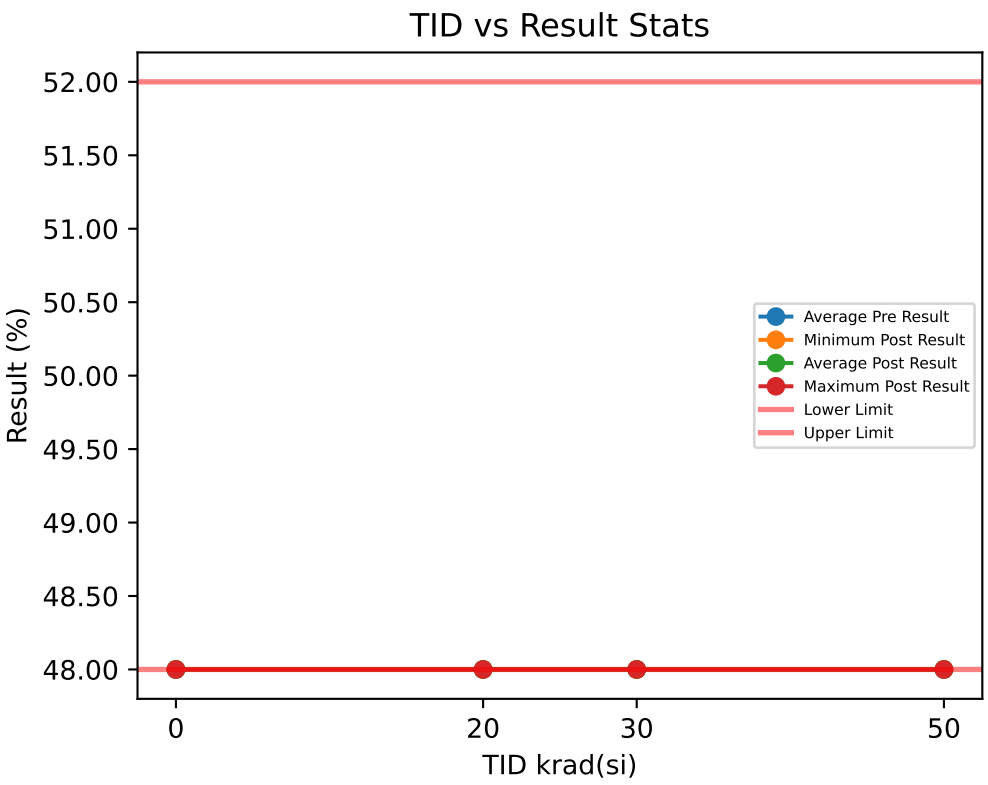
Test Results (Lower Limit = 80.0, Upper Limit = 110.0 (kHz))

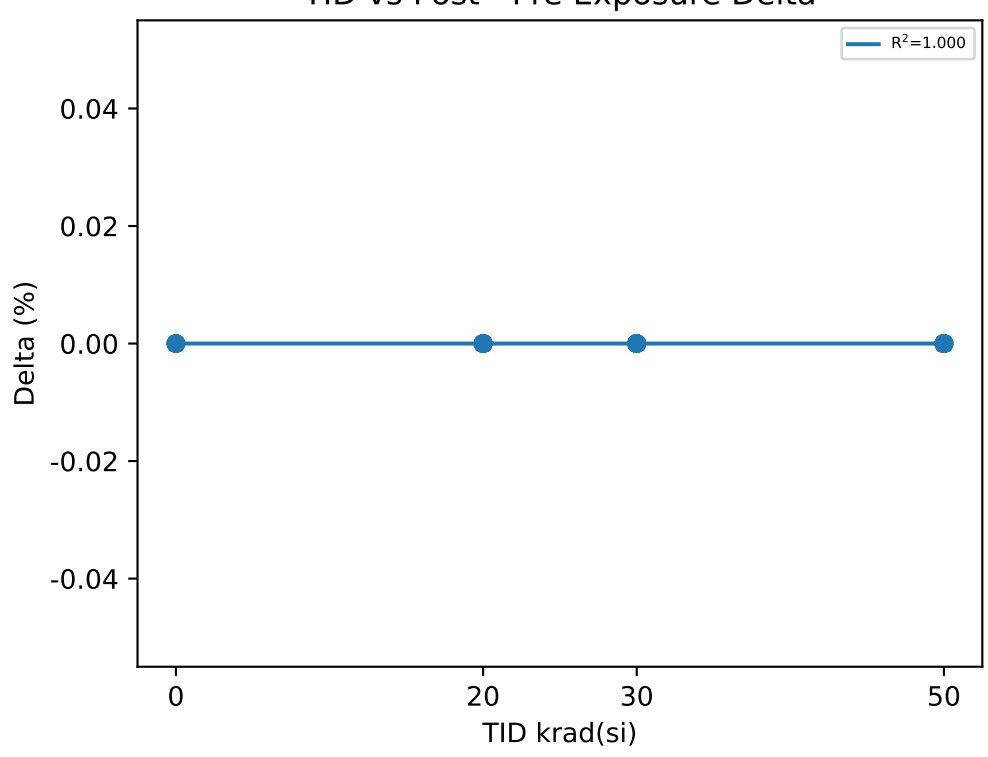
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	91.624	91.324	-0.2997
2	20	Unbiased	93.683	93.532	-0.1507
3	50	Biased	94.156	94.643	0.487
4	30	Unbiased	95.498	95.371	-0.1268
5	50	Unbiased	90.611	89.575	-1.0368
6	30	Biased	93.354	93.94	0.5858
7	50	Biased	93.907	93.697	-0.2105
8	30	Unbiased	94.648	94.715	0.0668
9	20	Unbiased	92.104	92.023	-0.0808
10	50	Biased	94.975	95.203	0.2279
11	30	Biased	95.612	96.255	0.6431
12	0	Correlation	90.194	90.188	-0.0066
13	0	Correlation	92.826	92.831	0.0048
14	50	Unbiased	95.754	95.69	-0.0643
15	20	Biased	93.121	93.413	0.2922
16	20	Unbiased	92.541	92.862	0.3209
17	20	Biased	95.578	95.171	-0.4064
18	20	Unbiased	93.806	93.377	-0.4292
19	20	Biased	93.291	93.092	-0.1989
20	50	Unbiased	93.021	92.396	-0.6254
21	0	Correlation	92.835	92.855	0.0198
22	50	Unbiased	92.56	92.576	0.0157
23	0	Correlation	94.943	94.944	0.0006
24	20	Biased	93.565	93.588	0.0234
26	50	Biased	93.417	94.192	0.7756
27	30	Unbiased	92.686	92.66	-0.0251
28	30	Biased	97.43	97.457	0.0269
29	30	Unbiased	97.498	97.356	-0.1421
30	20	Biased	92.828	93.037	0.2089
31	30	Unbiased	96.583	96.588	0.0054
33	30	Biased	94.282	94.531	0.2489
34	50	Unbiased	91.153	92.072	0.9192
35	20	Unbiased	93.511	93.543	0.0314
41	30	Biased	93.819	91.493	-2.3257

Test Statistics (kHz)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	90.194	92.7	94.943	1.9447	90.188	92.704	94.944	1.9483	-0.0066	0.00465	0.0198	0.011143
20	92.104	93.403	95.578	0.9346	92.023	93.364	95.171	0.78951	-0.4292	-0.03892	0.3209	0.26595
30	92.686	95.141	97.498	1.6725	91.493	95.037	97.457	1.9722	-2.3257	-0.10428	0.6431	0.82737
50	90.611	93.118	95.754	1.6628	89.575	93.137	95.69	1.899	-1.0368	0.01887	0.9192	0.60888

Device Test: 20.29 PF|DCL_48/SYNC/14/14/0/0/5/100kHz//@DUTY_SYNC_EXT_DCL50





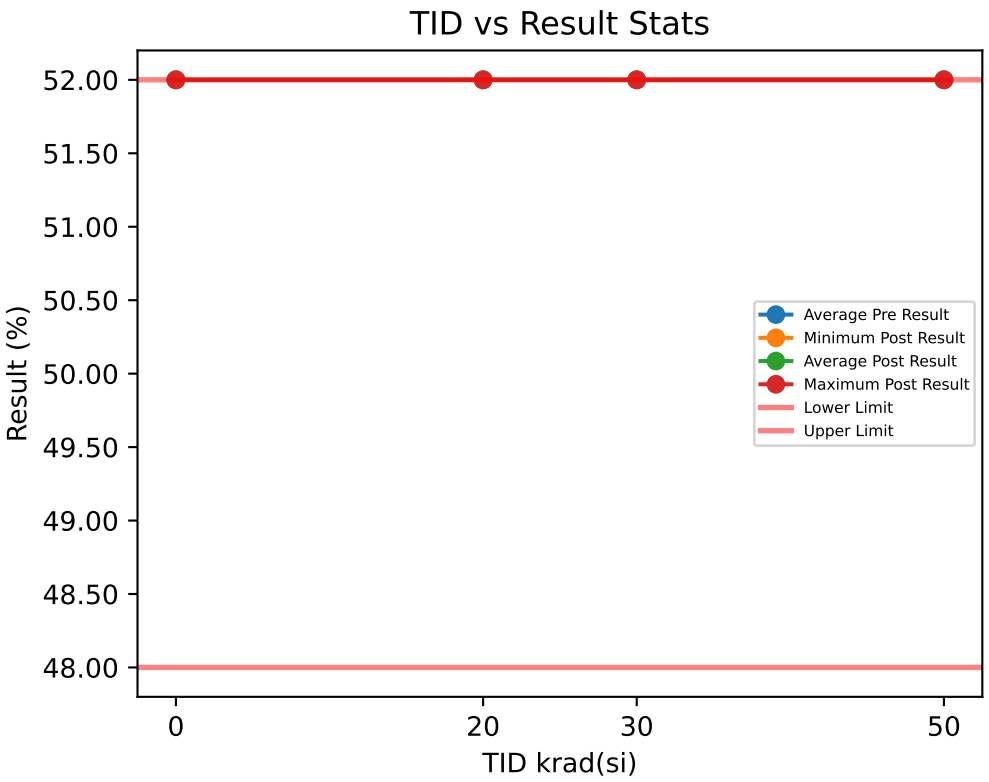
Test Results (Lower Limit = 48.0, Upper Limit = 52.0 (%))

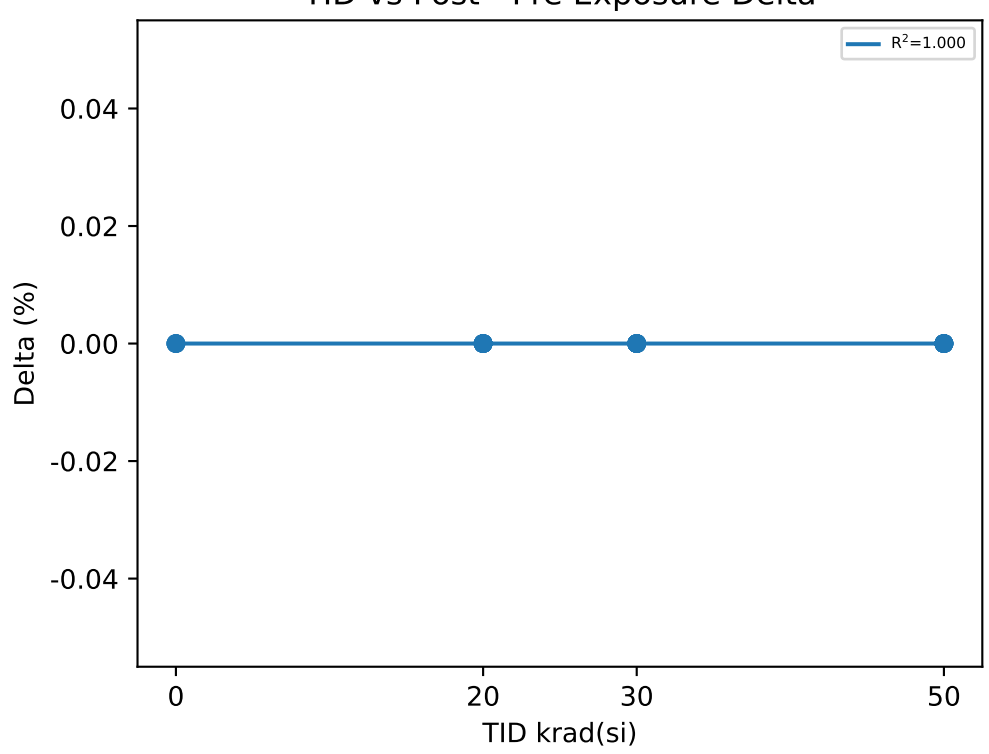
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	48	48	0
2	20	Unbiased	48	48	0
3	50	Biased	48	48	0
4	30	Unbiased	48	48	0
5	50	Unbiased	48	48	0
6	30	Biased	48	48	0
7	50	Biased	48	48	0
8	30	Unbiased	48	48	0
9	20	Unbiased	48	48	0
10	50	Biased	48	48	0
11	30	Biased	48	48	0
12	0	Correlation	48	48	0
13	0	Correlation	48	48	0
14	50	Unbiased	48	48	0
15	20	Biased	48	48	0
16	20	Unbiased	48	48	0
17	20	Biased	48	48	0
18	20	Unbiased	48	48	0
19	20	Biased	48	48	0
20	50	Unbiased	48	48	0
21	0	Correlation	48	48	0
22	50	Unbiased	48	48	0
23	0	Correlation	48	48	0
24	20	Biased	48	48	0
26	50	Biased	48	48	0
27	30	Unbiased	48	48	0
28	30	Biased	48	48	0
29	30	Unbiased	48	48	0
30	20	Biased	48	48	0
31	30	Unbiased	48	48	0
33	30	Biased	48	48	0
34	50	Unbiased	48	48	0
35	20	Unbiased	48	48	0
41	30	Biased	48	48	0

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	48	48	48	0	48	48	48	0	0	0	0	0
20	48	48	48	0	48	48	48	0	0	0	0	0
30	48	48	48	0	48	48	48	0	0	0	0	0
50	48	48	48	0	48	48	48	0	0	0	0	0

Device Test: 20.30 PF|DCL_52/SYNC/14/14/0/0/5/100kHz//@DUTY_SYNC_EXT_DCL50





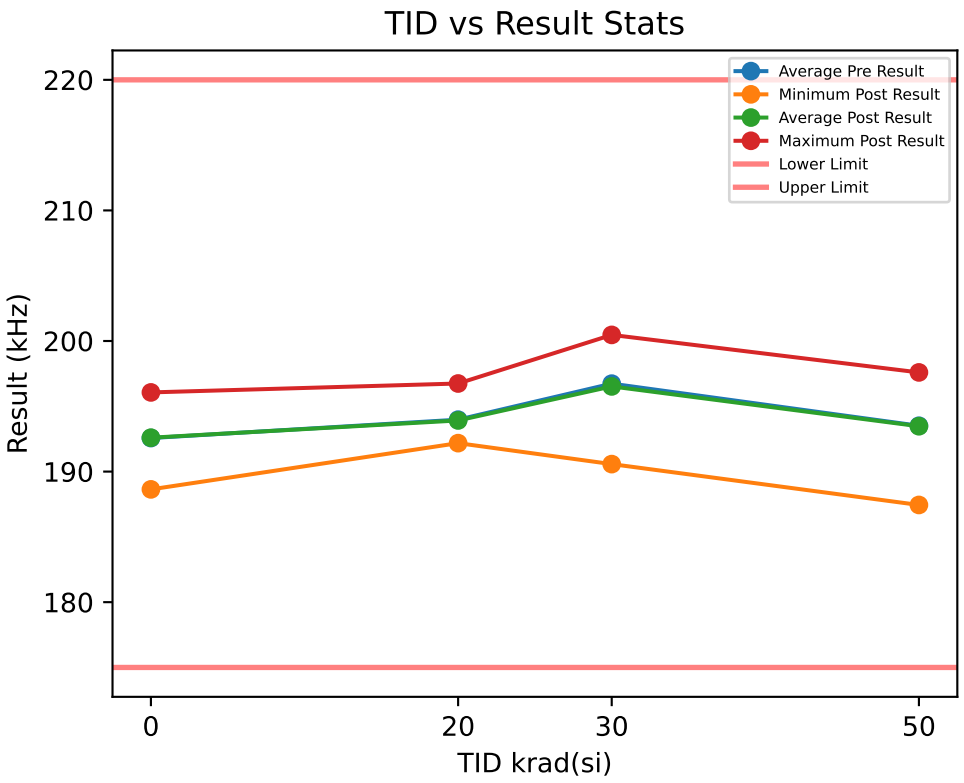
Test Results (Lower Limit = 48.0, Upper Limit = 52.0 (%))

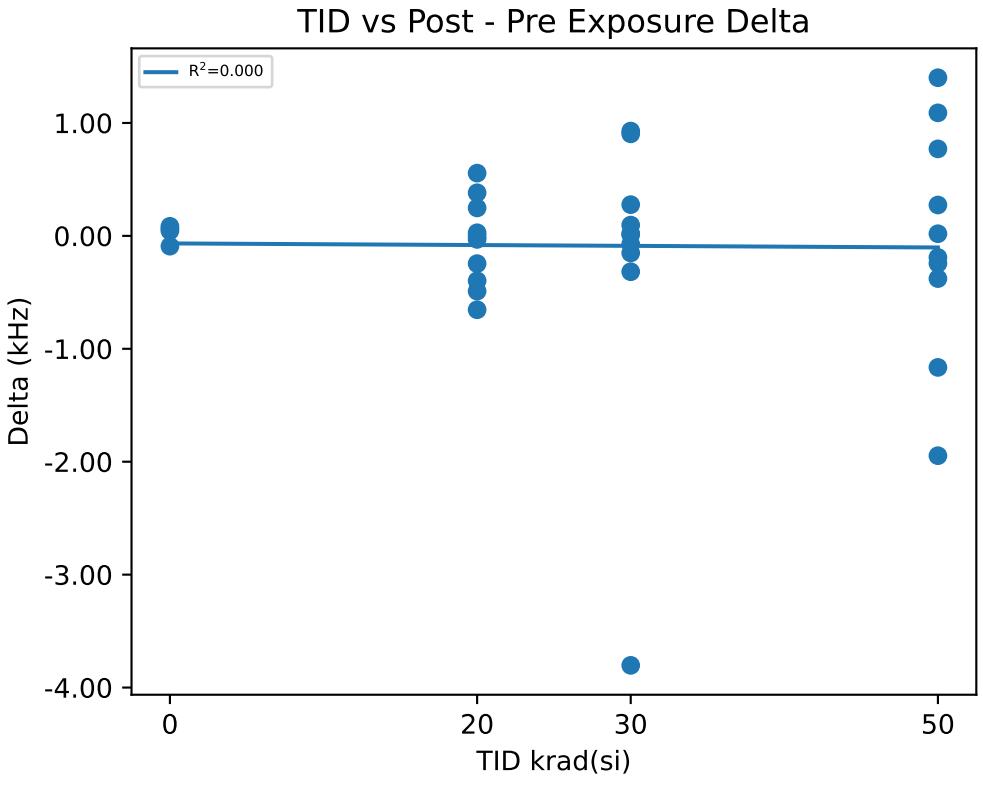
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	52	52	0
2	20	Unbiased	52	52	0
3	50	Biased	52	52	0
4	30	Unbiased	52	52	0
5	50	Unbiased	52	52	0
6	30	Biased	52	52	0
7	50	Biased	52	52	0
8	30	Unbiased	52	52	0
9	20	Unbiased	52	52	0
10	50	Biased	52	52	0
11	30	Biased	52	52	0
12	0	Correlation	52	52	0
13	0	Correlation	52	52	0
14	50	Unbiased	52	52	0
15	20	Biased	52	52	0
16	20	Unbiased	52	52	0
17	20	Biased	52	52	0
18	20	Unbiased	52	52	0
19	20	Biased	52	52	0
20	50	Unbiased	52	52	0
21	0	Correlation	52	52	0
22	50	Unbiased	52	52	0
23	0	Correlation	52	52	0
24	20	Biased	52	52	0
26	50	Biased	52	52	0
27	30	Unbiased	52	52	0
28	30	Biased	52	52	0
29	30	Unbiased	52	52	0
30	20	Biased	52	52	0
31	30	Unbiased	52	52	0
33	30	Biased	52	52	0
34	50	Unbiased	52	52	0
35	20	Unbiased	52	52	0
41	30	Biased	52	52	0

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	52	52	52	0	52	52	52	0	0	0	0	0
20	52	52	52	0	52	52	52	0	0	0	0	0
30	52	52	52	0	52	52	52	0	0	0	0	0
50	52	52	52	0	52	52	52	0	0	0	0	0

Device Test: 20.31 LEVEL|FREQ/RT/4.5/4.5/0/0/4.5/200kHz//@FSW_EXT_RT_B





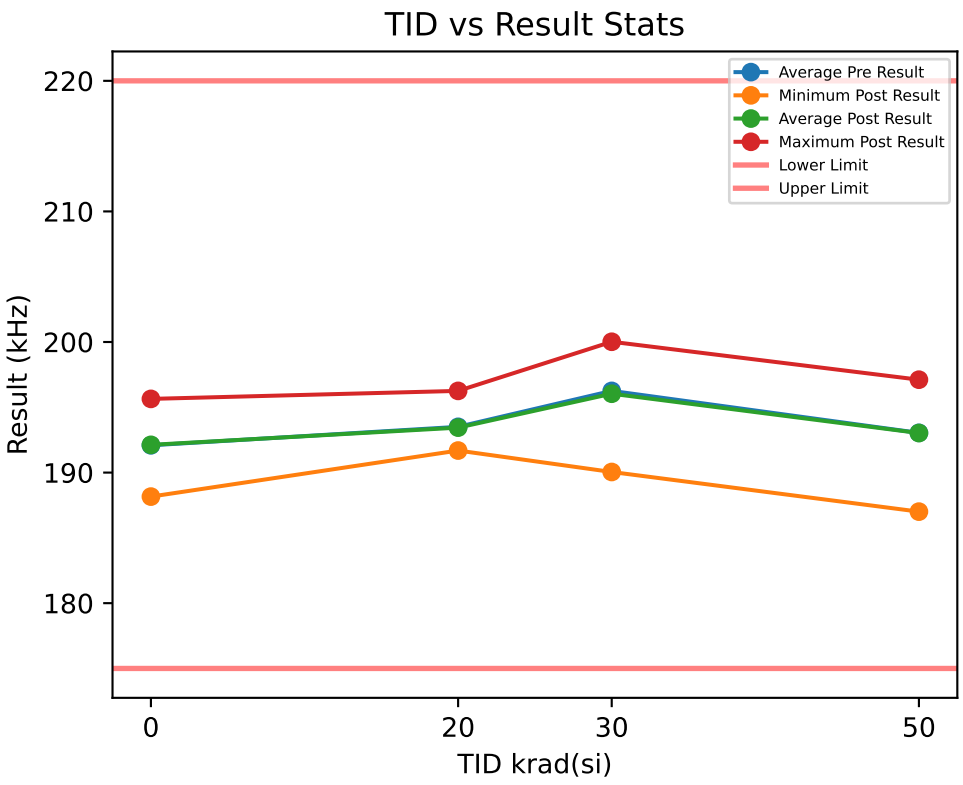
Test Results (Lower Limit = 175.0, Upper Limit = 220.0 (kHz))

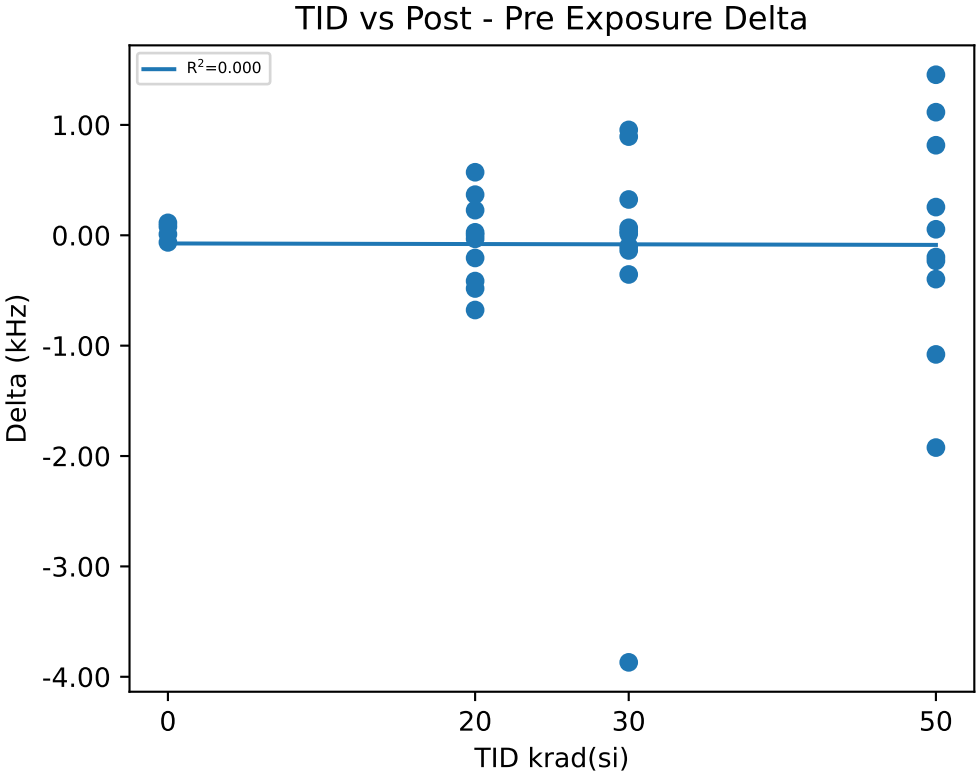
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	191.01	190.63	-0.3782
2	20	Unbiased	194.61	194.21	-0.3975
3	50	Biased	195.61	196.38	0.7705
4	30	Unbiased	197.7	197.55	-0.1515
5	50	Unbiased	189.39	187.44	-1.9467
6	30	Biased	193.85	194.78	0.9284
7	50	Biased	194.73	194.48	-0.2436
8	30	Unbiased	195.66	195.68	0.0209
9	20	Unbiased	192.21	192.18	-0.0311
10	50	Biased	196.4	196.68	0.2735
11	30	Biased	197.63	198.54	0.9035
12	0	Correlation	188.73	188.64	-0.0912
13	0	Correlation	192.36	192.4	0.0452
14	50	Unbiased	197.79	197.59	-0.1908
15	20	Biased	193.42	193.8	0.3818
16	20	Unbiased	192.2	192.75	0.5558
17	20	Biased	197.23	196.75	-0.4893
18	20	Unbiased	194.18	193.53	-0.6542
19	20	Biased	194.52	194.28	-0.2457
20	50	Unbiased	193.28	192.12	-1.1647
21	0	Correlation	193.19	193.28	0.0849
22	50	Unbiased	192.53	192.55	0.0191
23	0	Correlation	196	196.06	0.0645
24	20	Biased	194.62	194.62	-0.0057
26	50	Biased	193.78	194.87	1.0896
27	30	Unbiased	192.7	192.71	0.0109
28	30	Biased	200.15	200.08	-0.0729
29	30	Unbiased	200.78	200.47	-0.3174
30	20	Biased	192.47	192.72	0.2474
31	30	Unbiased	198.92	199.02	0.0957
33	30	Biased	195.55	195.83	0.2766
34	50	Unbiased	190.58	191.98	1.4005
35	20	Unbiased	194.29	194.32	0.0276
41	30	Biased	194.38	190.57	-3.8034

Test Statistics (kHz)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	188.73	192.57	196	2.9969	188.64	192.59	196.06	3.0655	-0.0912	0.02585	0.0849	0.079699
20	192.2	193.98	197.23	1.5177	192.18	193.91	196.75	1.2842	-0.6542	-0.06109	0.5558	0.3896
30	192.7	196.73	200.78	2.7339	190.57	196.52	200.47	3.2261	-3.8034	-0.21092	0.9284	1.3298
50	189.39	193.51	197.79	2.6968	187.44	193.47	197.59	3.1277	-1.9467	-0.03708	1.4005	1.0104

Device Test: 20.33 LEVEL|FREQ/RT/5/5/0/0/5/200kHz//@FSW_EXT_RT_B





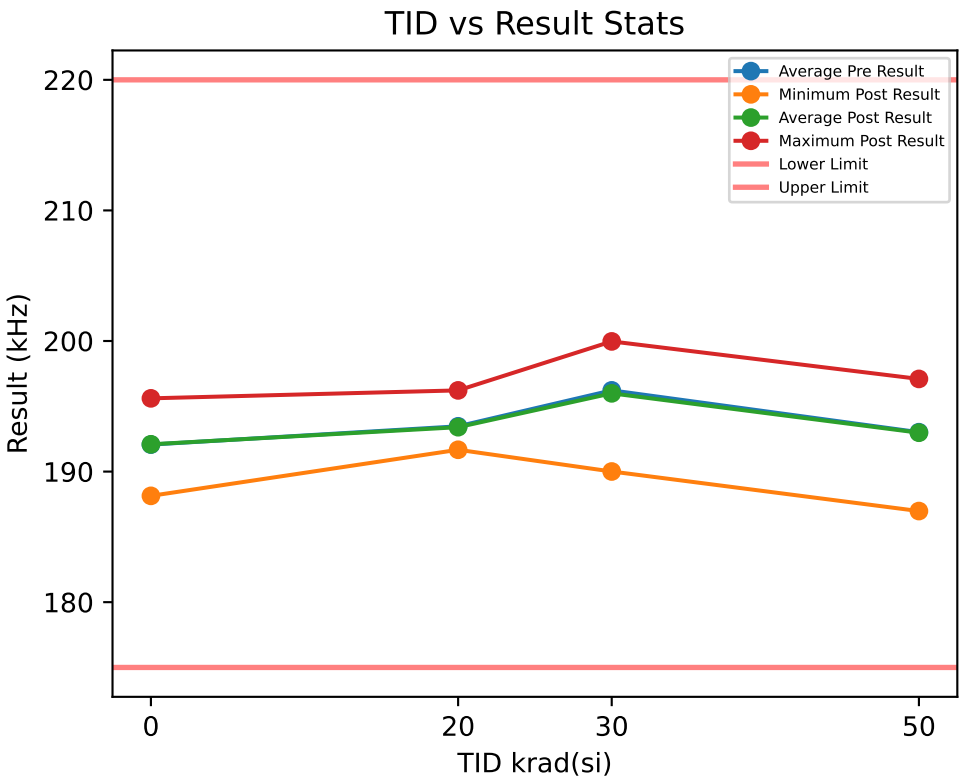
Test Results (Lower Limit = 175.0, Upper Limit = 220.0 (kHz))

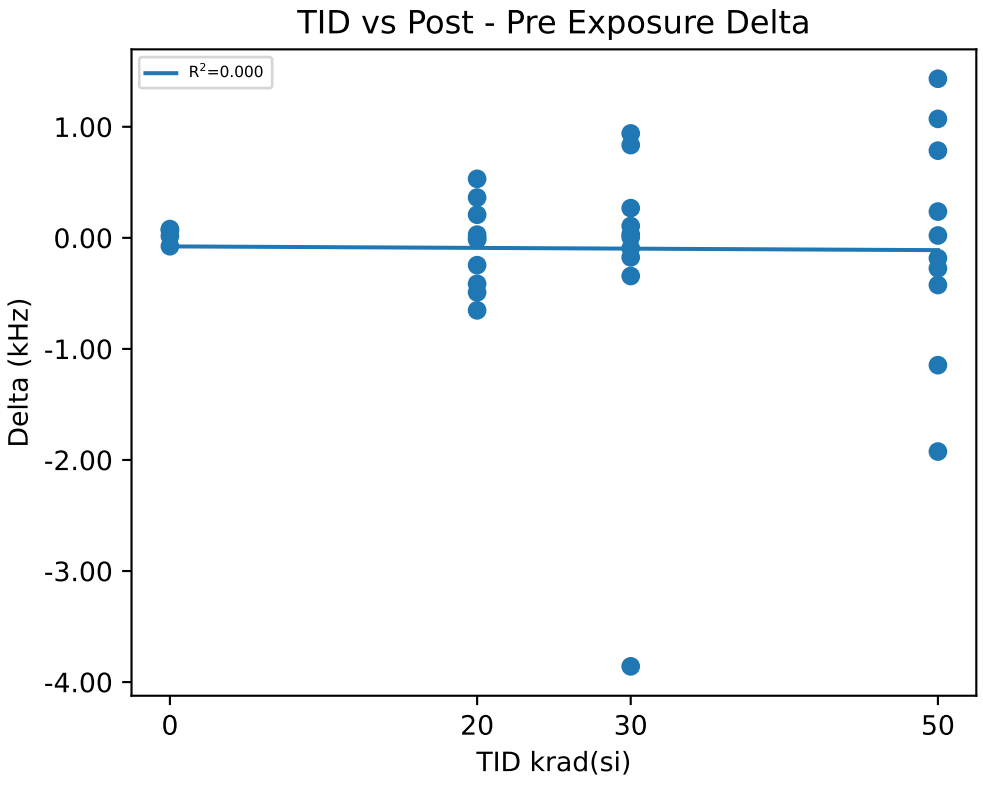
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	190.55	190.15	-0.3973
2	20	Unbiased	194.17	193.76	-0.4148
3	50	Biased	195.09	195.9	0.8158
4	30	Unbiased	197.21	197.08	-0.1374
5	50	Unbiased	188.93	187.01	-1.9234
6	30	Biased	193.37	194.32	0.9548
7	50	Biased	194.26	194.03	-0.231
8	30	Unbiased	195.16	195.2	0.0373
9	20	Unbiased	191.72	191.69	-0.0321
10	50	Biased	195.96	196.22	0.2554
11	30	Biased	197.16	198.05	0.894
12	0	Correlation	188.23	188.16	-0.0643
13	0	Correlation	191.86	191.87	0.0096
14	50	Unbiased	197.31	197.11	-0.1971
15	20	Biased	192.9	193.26	0.3682
16	20	Unbiased	191.79	192.36	0.5711
17	20	Biased	196.74	196.26	-0.4821
18	20	Unbiased	193.74	193.07	-0.677
19	20	Biased	194.06	193.85	-0.2054
20	50	Unbiased	192.81	191.73	-1.0793
21	0	Correlation	192.71	192.82	0.1127
22	50	Unbiased	192.09	192.15	0.0544
23	0	Correlation	195.56	195.64	0.0793
24	20	Biased	194.11	194.13	0.027
26	50	Biased	193.31	194.43	1.1153
27	30	Unbiased	192.17	192.19	0.0134
28	30	Biased	199.7	199.6	-0.0994
29	30	Unbiased	200.37	200.02	-0.355
30	20	Biased	191.98	192.21	0.2276
31	30	Unbiased	198.41	198.48	0.0679
33	30	Biased	195.09	195.42	0.3244
34	50	Unbiased	190.11	191.56	1.4546
35	20	Unbiased	193.83	193.83	0.0028
41	30	Biased	193.91	190.05	-3.8693

Test Statistics (kHz)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	188.23	192.09	195.56	3.0243	188.16	192.12	195.64	3.0898	-0.0643	0.034325	0.1127	0.078536
20	191.72	193.5	196.74	1.5104	191.69	193.44	196.26	1.2798	-0.677	-0.06147	0.5711	0.39193
30	192.17	196.26	200.37	2.7536	190.05	196.04	200.02	3.2387	-3.8693	-0.21693	0.9548	1.3531
50	188.93	193.04	197.31	2.69	187.01	193.03	197.11	3.1122	-1.9234	-0.01326	1.4546	1.0114

Device Test: 20.35 LEVEL|FREQ/RT/12/12/0/0/5/200kHz//@FSW_EXT_RT_B





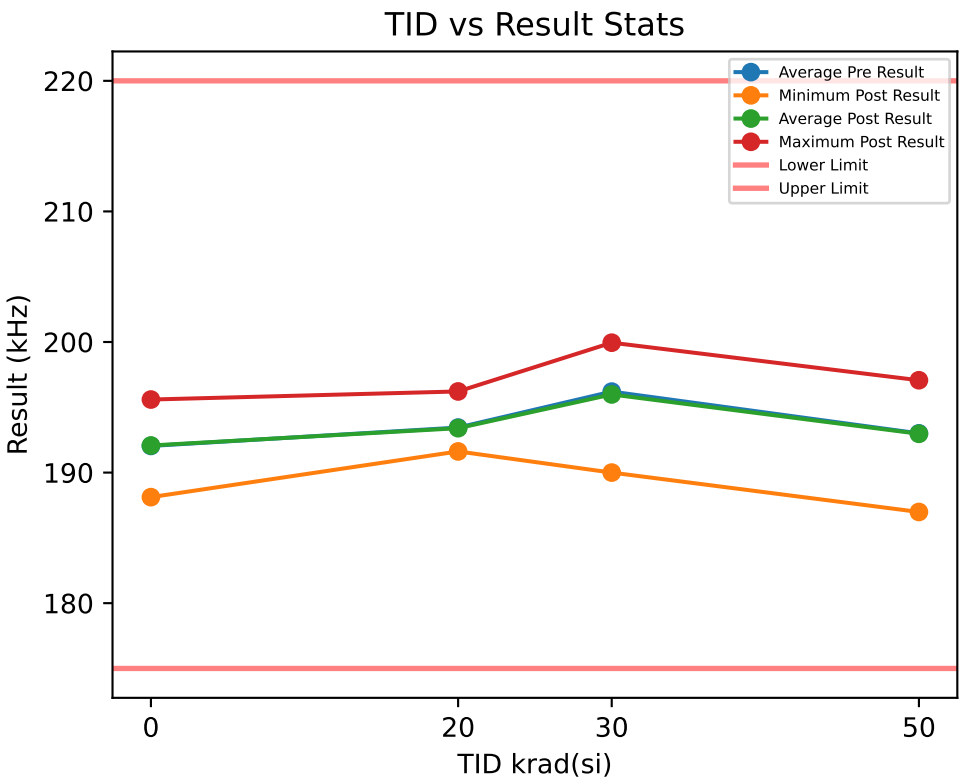
Test Results (Lower Limit = 175.0, Upper Limit = 220.0 (kHz))

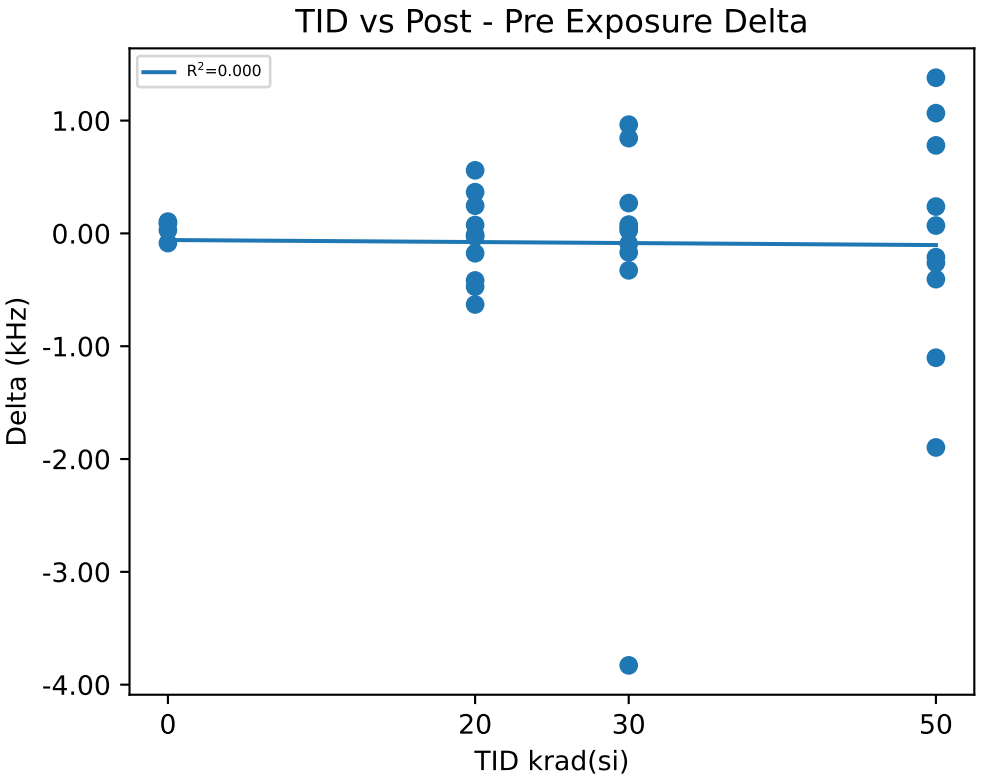
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	190.53	190.11	-0.4249
2	20	Unbiased	194.12	193.71	-0.414
3	50	Biased	195.07	195.85	0.7851
4	30	Unbiased	197.19	197.02	-0.1755
5	50	Unbiased	188.9	186.98	-1.9242
6	30	Biased	193.34	194.28	0.9402
7	50	Biased	194.21	193.94	-0.2746
8	30	Unbiased	195.12	195.13	0.0056
9	20	Unbiased	191.69	191.67	-0.016
10	50	Biased	195.95	196.19	0.2366
11	30	Biased	197.15	197.99	0.8352
12	0	Correlation	188.22	188.14	-0.0756
13	0	Correlation	191.81	191.83	0.0155
14	50	Unbiased	197.28	197.1	-0.1832
15	20	Biased	192.87	193.24	0.3627
16	20	Unbiased	191.76	192.3	0.5314
17	20	Biased	196.71	196.22	-0.4911
18	20	Unbiased	193.71	193.05	-0.6527
19	20	Biased	194	193.75	-0.246
20	50	Unbiased	192.79	191.64	-1.1464
21	0	Correlation	192.71	192.78	0.0681
22	50	Unbiased	192.05	192.07	0.0212
23	0	Correlation	195.53	195.61	0.0791
24	20	Biased	194.06	194.06	0.0014
26	50	Biased	193.29	194.36	1.0712
27	30	Unbiased	192.14	192.17	0.0324
28	30	Biased	199.65	199.56	-0.0929
29	30	Unbiased	200.31	199.97	-0.3436
30	20	Biased	191.97	192.18	0.208
31	30	Unbiased	198.36	198.46	0.1065
33	30	Biased	195.07	195.34	0.2676
34	50	Unbiased	190.09	191.52	1.4327
35	20	Unbiased	193.79	193.82	0.0291
41	30	Biased	193.87	190.01	-3.8584

Test Statistics (kHz)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	188.22	192.07	195.53	3.0165	188.14	192.09	195.61	3.0834	-0.0756	0.021775	0.0791	0.070601
20	191.69	193.47	196.71	1.5057	191.67	193.4	196.22	1.2749	-0.6527	-0.06872	0.5314	0.38155
30	192.14	196.22	200.31	2.7471	190.01	195.99	199.97	3.2351	-3.8584	-0.22829	0.9402	1.3412
50	188.9	193.02	197.28	2.6908	186.98	192.98	197.1	3.1154	-1.9242	-0.04065	1.4327	1.009

Device Test: 20.37 LEVEL|FREQ/RT/14/14/0/0/5/200kHz//@FSW_EXT_RT_B





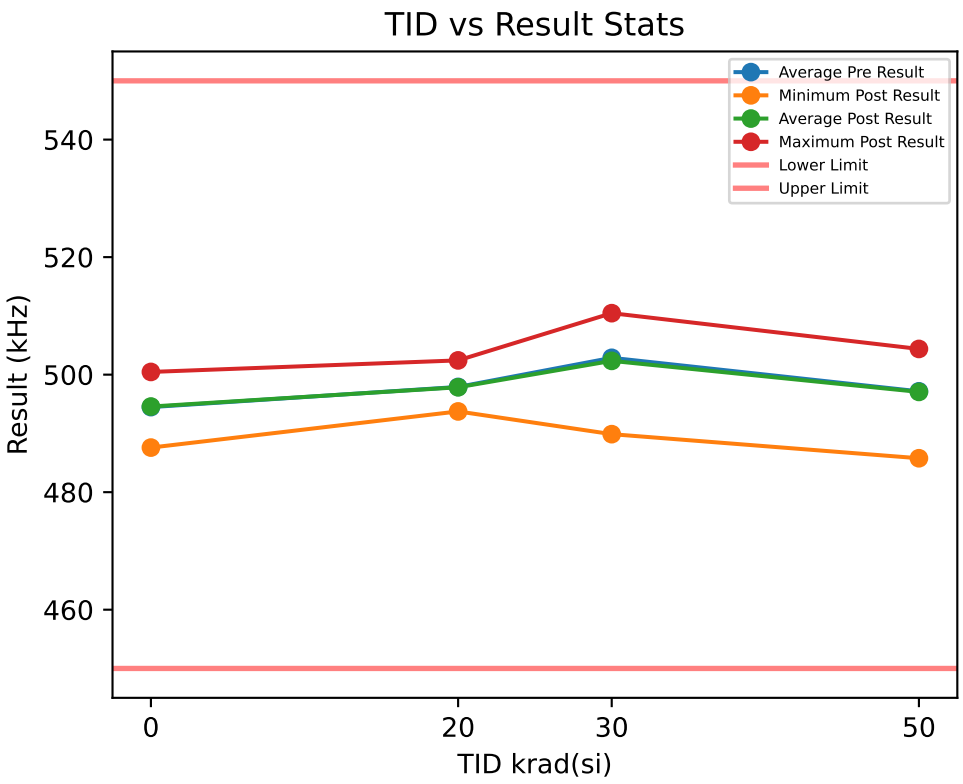
Test Results (Lower Limit = 175.0, Upper Limit = 220.0 (kHz))

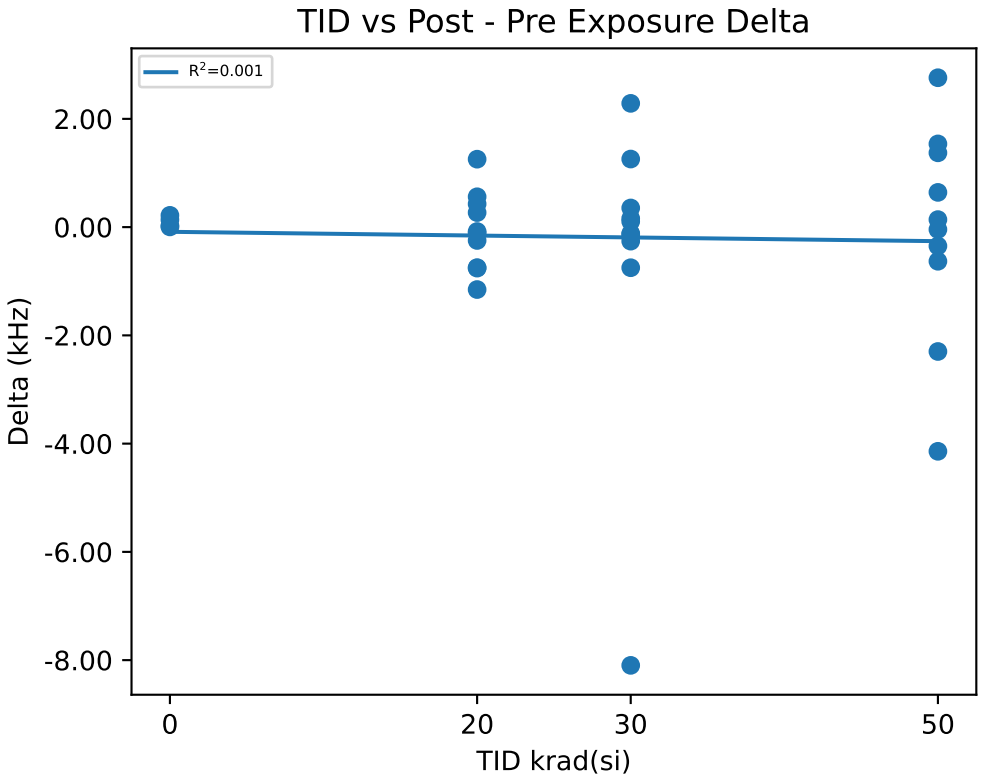
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	190.52	190.11	-0.4057
2	20	Unbiased	194.12	193.7	-0.4169
3	50	Biased	195.07	195.85	0.7802
4	30	Unbiased	197.19	197.02	-0.1685
5	50	Unbiased	188.88	186.98	-1.8973
6	30	Biased	193.3	194.26	0.964
7	50	Biased	194.21	193.95	-0.2615
8	30	Unbiased	195.1	195.14	0.0476
9	20	Unbiased	191.65	191.62	-0.0302
10	50	Biased	195.94	196.17	0.2379
11	30	Biased	197.12	197.97	0.8445
12	0	Correlation	188.21	188.12	-0.0857
13	0	Correlation	191.8	191.82	0.0276
14	50	Unbiased	197.28	197.07	-0.2103
15	20	Biased	192.88	193.24	0.3656
16	20	Unbiased	191.73	192.29	0.5592
17	20	Biased	196.69	196.21	-0.4721
18	20	Unbiased	193.67	193.04	-0.63
19	20	Biased	193.98	193.8	-0.1761
20	50	Unbiased	192.74	191.63	-1.1021
21	0	Correlation	192.66	192.76	0.1045
22	50	Unbiased	192.01	192.08	0.0695
23	0	Correlation	195.51	195.59	0.0876
24	20	Biased	194.05	194.12	0.0745
26	50	Biased	193.3	194.36	1.0659
27	30	Unbiased	192.12	192.15	0.0261
28	30	Biased	199.65	199.55	-0.0918
29	30	Unbiased	200.28	199.95	-0.3275
30	20	Biased	191.93	192.17	0.2457
31	30	Unbiased	198.37	198.44	0.078
33	30	Biased	195.07	195.34	0.269
34	50	Unbiased	190.12	191.5	1.3798
35	20	Unbiased	193.8	193.79	-0.0113
41	30	Biased	193.83	190	-3.8288

Test Statistics (kHz)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	188.21	192.04	195.51	3.0088	188.12	192.07	195.59	3.0854	-0.0857	0.0335	0.1045	0.086045
20	191.65	193.45	196.69	1.5119	191.62	193.4	196.21	1.2871	-0.63	-0.04916	0.5592	0.38206
30	192.12	196.2	200.28	2.7524	190	195.98	199.95	3.2343	-3.8288	-0.21874	0.964	1.3354
50	188.88	193.01	197.28	2.6931	186.98	192.97	197.07	3.1095	-1.8973	-0.03436	1.3798	0.98826

Device Test: 20.39 LEVEL|FREQ/RT/4.5/4.5/0/0/4.5/500kHz//@FSW_EXT_RT_C





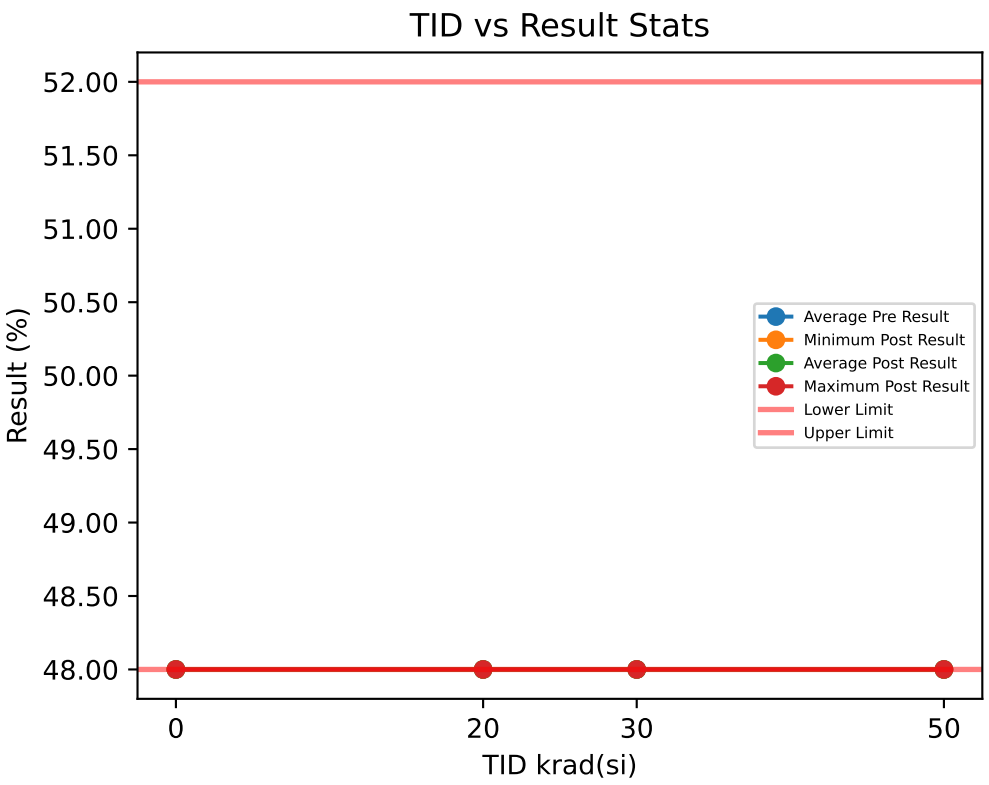
Test Results (Lower Limit = 450.0, Upper Limit = 550.0 (kHz))

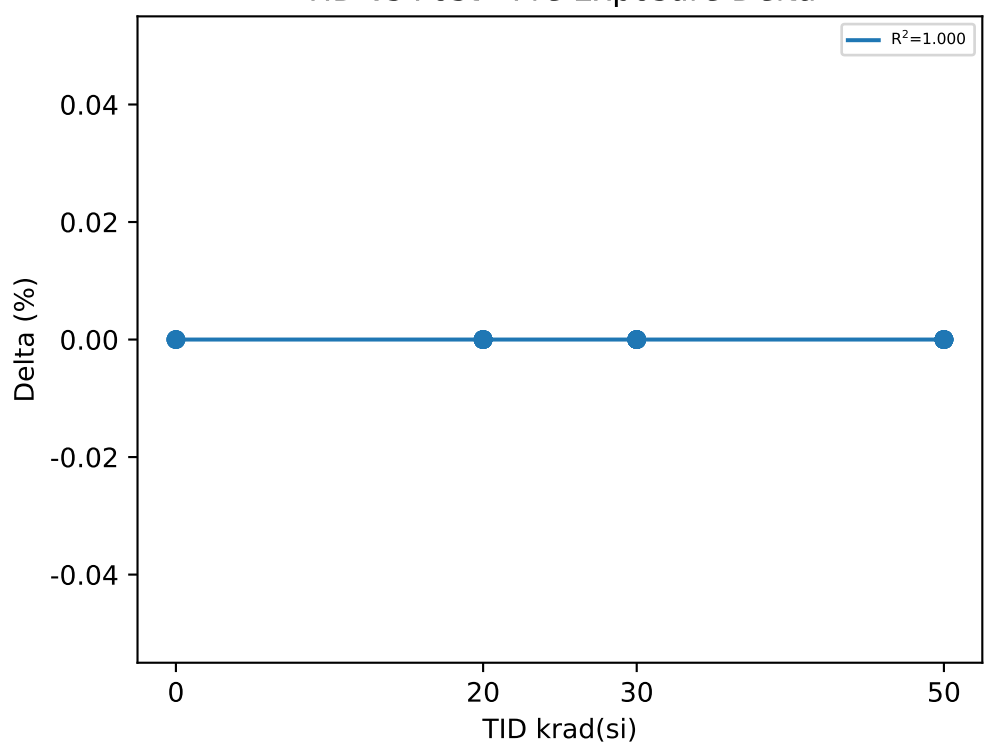
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	492.57	492.22	-0.3488
2	20	Unbiased	499.74	498.98	-0.7573
3	50	Biased	502.39	503.77	1.3727
4	30	Unbiased	505.59	505.47	-0.1178
5	50	Unbiased	489.91	485.77	-4.1418
6	30	Biased	497.63	499.91	2.2865
7	50	Biased	499.32	499.27	-0.0432
8	30	Unbiased	499.77	499.64	-0.1342
9	20	Unbiased	495.39	495.14	-0.2465
10	50	Biased	501.92	502.56	0.6417
11	30	Biased	505.19	506.45	1.2578
12	0	Correlation	487.37	487.59	0.2177
13	0	Correlation	492.9	493.04	0.1372
14	50	Unbiased	505.01	504.37	-0.6308
15	20	Biased	497.03	497.45	0.4281
16	20	Unbiased	493.32	494.57	1.2551
17	20	Biased	503.17	502.43	-0.7488
18	20	Unbiased	497.28	496.13	-1.1532
19	20	Biased	501.14	501.03	-0.1095
20	50	Unbiased	496.01	493.71	-2.2976
21	0	Correlation	497.18	497.2	0.0256
22	50	Unbiased	494.67	494.81	0.1389
23	0	Correlation	500.46	500.46	0.0042
24	20	Biased	499.82	500.09	0.2687
26	50	Biased	497.17	498.71	1.5372
27	30	Unbiased	495.58	495.32	-0.2591
28	30	Biased	507.63	507.79	0.1602
29	30	Unbiased	511.21	510.46	-0.7502
30	20	Biased	493.18	493.74	0.5606
31	30	Unbiased	506.75	506.85	0.1049
33	30	Biased	501.3	501.66	0.3538
34	50	Unbiased	492.66	495.42	2.7598
35	20	Unbiased	499.02	498.93	-0.0815
41	30	Biased	497.97	489.87	-8.0964

Test Statistics (kHz)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	487.37	494.48	500.46	5.6577	487.59	494.57	500.46	5.5594	0.0042	0.096175	0.2177	0.099819
20	493.18	497.91	503.17	3.2898	493.74	497.85	502.43	2.918	-1.1532	-0.05843	1.2551	0.71913
30	495.58	502.86	511.21	5.129	489.87	502.34	510.46	6.3342	-8.0964	-0.51945	2.2865	2.7986
50	489.91	497.16	505.01	4.9179	485.77	497.06	504.37	5.833	-4.1418	-0.10119	2.7598	1.9762

Device Test: 20.41 PF|DCL_48/SYNC/4.5/4.5/0/0/4.5/500kHz//@DUTY_SYNC_EXT_DCL50





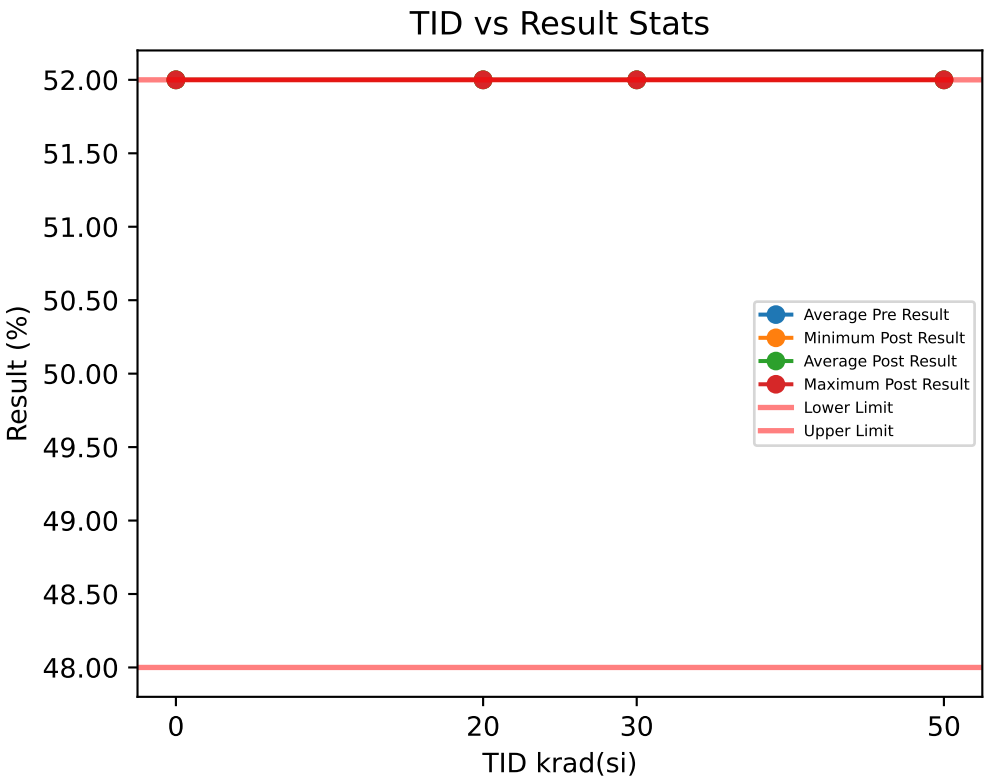
Test Results (Lower Limit = 48.0, Upper Limit = 52.0 (%))

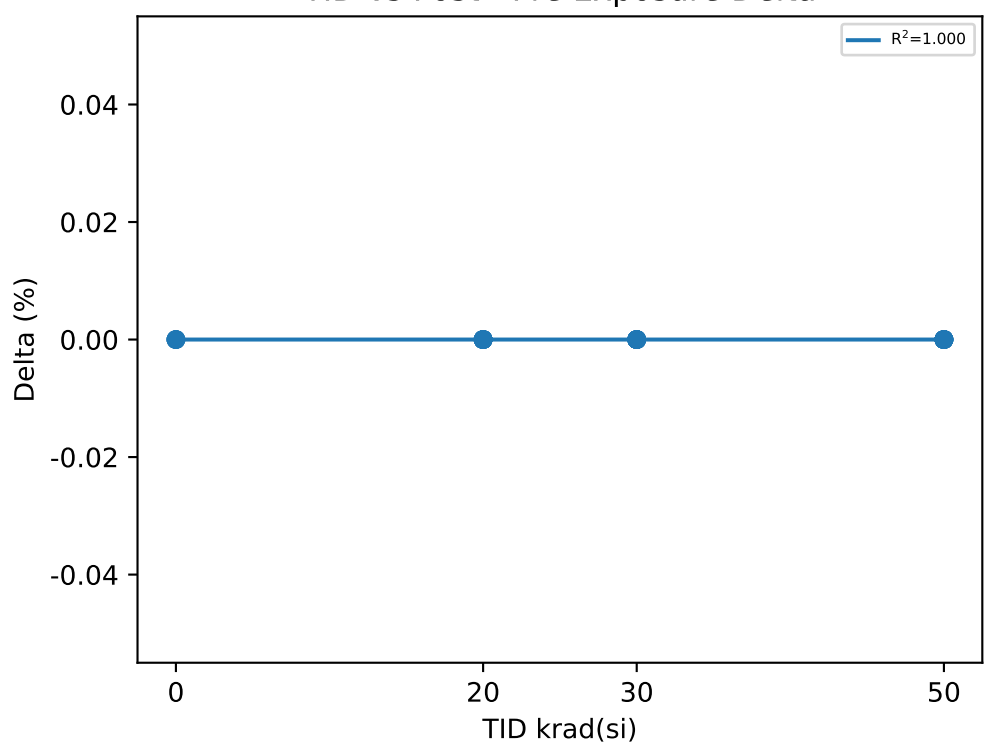
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	48	48	0
2	20	Unbiased	48	48	0
3	50	Biased	48	48	0
4	30	Unbiased	48	48	0
5	50	Unbiased	48	48	0
6	30	Biased	48	48	0
7	50	Biased	48	48	0
8	30	Unbiased	48	48	0
9	20	Unbiased	48	48	0
10	50	Biased	48	48	0
11	30	Biased	48	48	0
12	0	Correlation	48	48	0
13	0	Correlation	48	48	0
14	50	Unbiased	48	48	0
15	20	Biased	48	48	0
16	20	Unbiased	48	48	0
17	20	Biased	48	48	0
18	20	Unbiased	48	48	0
19	20	Biased	48	48	0
20	50	Unbiased	48	48	0
21	0	Correlation	48	48	0
22	50	Unbiased	48	48	0
23	0	Correlation	48	48	0
24	20	Biased	48	48	0
26	50	Biased	48	48	0
27	30	Unbiased	48	48	0
28	30	Biased	48	48	0
29	30	Unbiased	48	48	0
30	20	Biased	48	48	0
31	30	Unbiased	48	48	0
33	30	Biased	48	48	0
34	50	Unbiased	48	48	0
35	20	Unbiased	48	48	0
41	30	Biased	48	48	0

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	48	48	48	0	48	48	48	0	0	0	0	0
20	48	48	48	0	48	48	48	0	0	0	0	0
30	48	48	48	0	48	48	48	0	0	0	0	0
50	48	48	48	0	48	48	48	0	0	0	0	0

Device Test: 20.42 PF|DCL_52/SYNC/4.5/4.5/0/0/4.5/500kHz//@DUTY_SYNC_EXT_DCL50





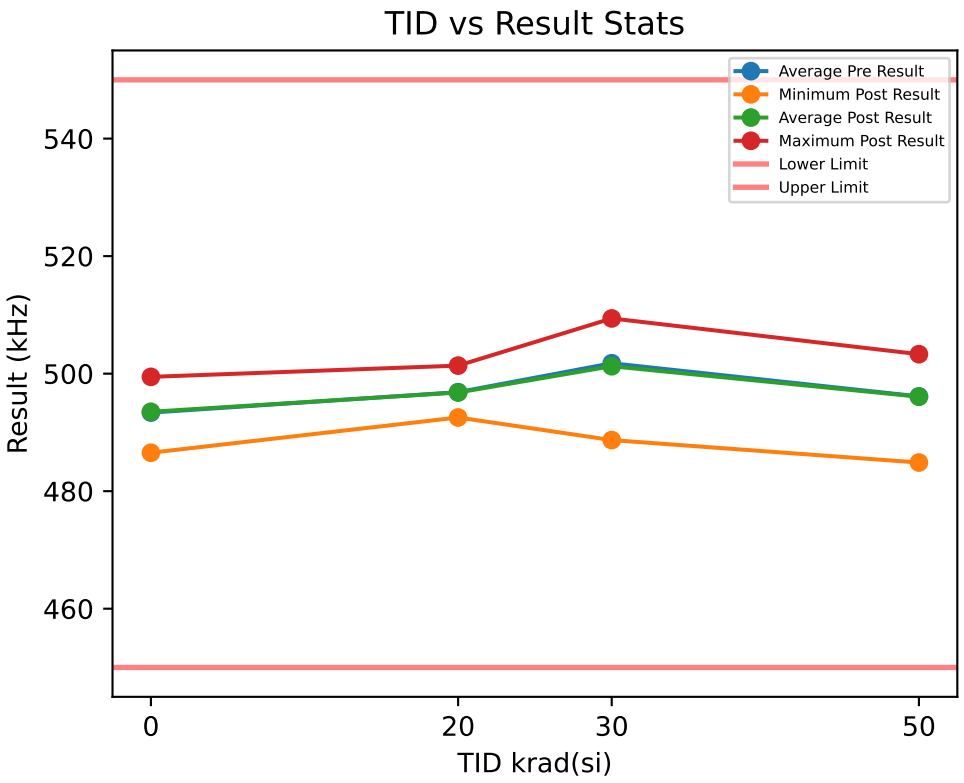
Test Results (Lower Limit = 48.0, Upper Limit = 52.0 (%))

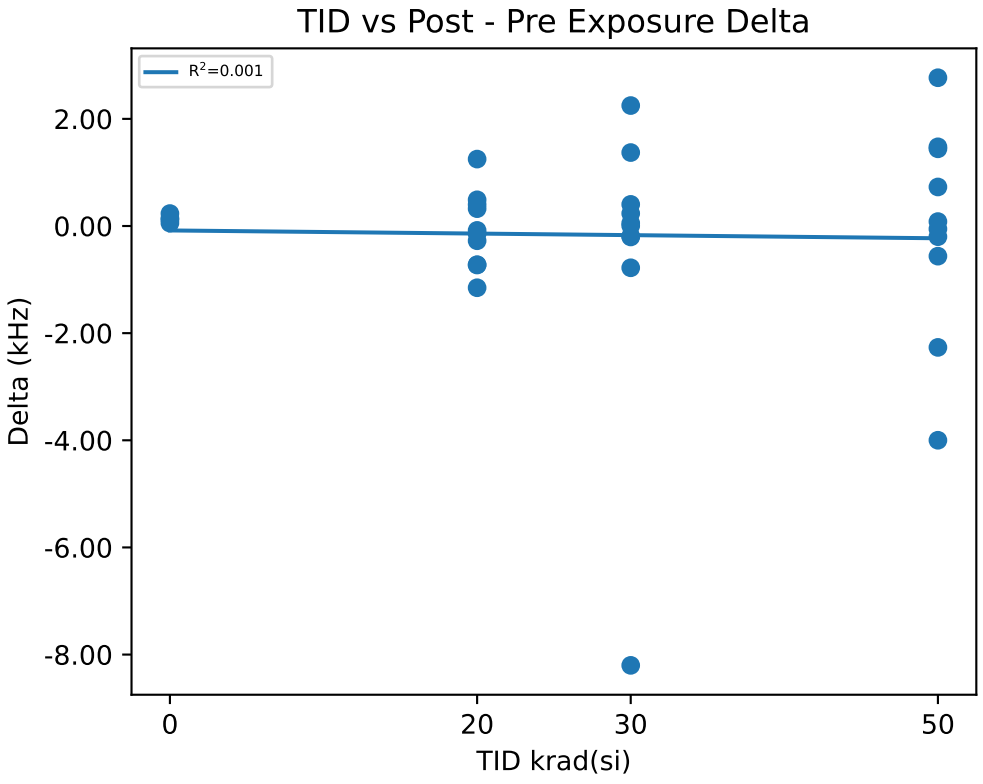
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	52	52	0
2	20	Unbiased	52	52	0
3	50	Biased	52	52	0
4	30	Unbiased	52	52	0
5	50	Unbiased	52	52	0
6	30	Biased	52	52	0
7	50	Biased	52	52	0
8	30	Unbiased	52	52	0
9	20	Unbiased	52	52	0
10	50	Biased	52	52	0
11	30	Biased	52	52	0
12	0	Correlation	52	52	0
13	0	Correlation	52	52	0
14	50	Unbiased	52	52	0
15	20	Biased	52	52	0
16	20	Unbiased	52	52	0
17	20	Biased	52	52	0
18	20	Unbiased	52	52	0
19	20	Biased	52	52	0
20	50	Unbiased	52	52	0
21	0	Correlation	52	52	0
22	50	Unbiased	52	52	0
23	0	Correlation	52	52	0
24	20	Biased	52	52	0
26	50	Biased	52	52	0
27	30	Unbiased	52	52	0
28	30	Biased	52	52	0
29	30	Unbiased	52	52	0
30	20	Biased	52	52	0
31	30	Unbiased	52	52	0
33	30	Biased	52	52	0
34	50	Unbiased	52	52	0
35	20	Unbiased	52	52	0
41	30	Biased	52	52	0

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	52	52	52	0	52	52	52	0	0	0	0	0
20	52	52	52	0	52	52	52	0	0	0	0	0
30	52	52	52	0	52	52	52	0	0	0	0	0
50	52	52	52	0	52	52	52	0	0	0	0	0

Device Test: 20.43 LEVEL|FREQ/RT/5/5/0/0/5/500kHz//@FSW_EXT_RT_C





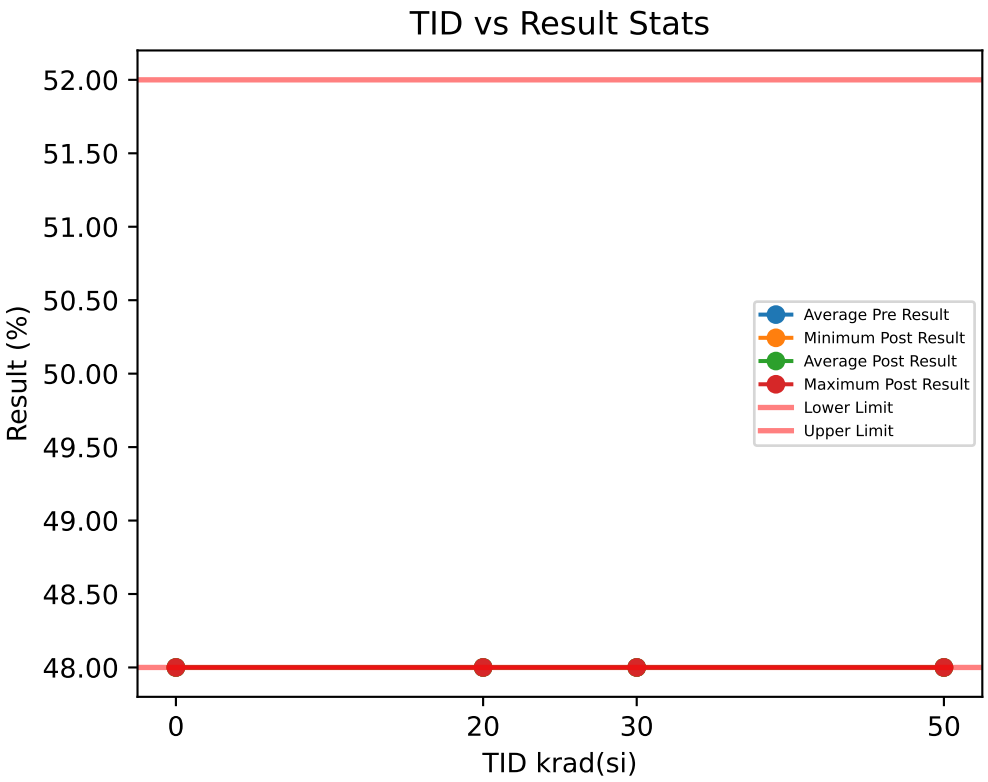
Test Results (Lower Limit = 450.0, Upper Limit = 550.0 (kHz))

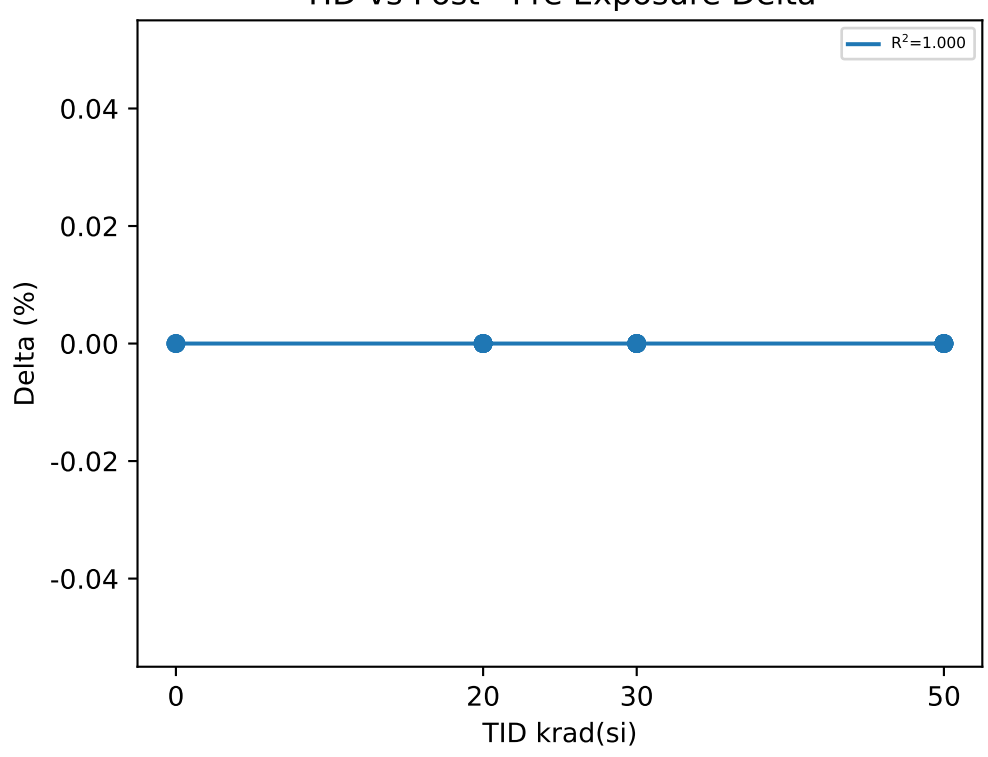
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	491.52	491.32	-0.1991
2	20	Unbiased	498.7	497.97	-0.7226
3	50	Biased	501.26	502.7	1.441
4	30	Unbiased	504.58	504.38	-0.2042
5	50	Unbiased	488.87	484.87	-3.9993
6	30	Biased	496.53	498.78	2.2487
7	50	Biased	498.19	498.14	-0.0543
8	30	Unbiased	498.54	498.54	0.0046
9	20	Unbiased	494.22	493.95	-0.2751
10	50	Biased	500.87	501.6	0.7288
11	30	Biased	504.05	505.42	1.3713
12	0	Correlation	486.31	486.54	0.2326
13	0	Correlation	491.78	491.92	0.1436
14	50	Unbiased	503.88	503.31	-0.5628
15	20	Biased	495.92	496.32	0.4004
16	20	Unbiased	492.41	493.65	1.2492
17	20	Biased	502.09	501.37	-0.7275
18	20	Unbiased	496.23	495.07	-1.1524
19	20	Biased	500.24	500.09	-0.1456
20	50	Unbiased	495.09	492.82	-2.2659
21	0	Correlation	496.06	496.12	0.0546
22	50	Unbiased	493.81	493.89	0.0828
23	0	Correlation	499.33	499.45	0.1186
24	20	Biased	498.69	499.02	0.3239
26	50	Biased	496.16	497.64	1.4782
27	30	Unbiased	494.42	494.23	-0.1885
28	30	Biased	506.57	506.81	0.2346
29	30	Unbiased	510.18	509.4	-0.7797
30	20	Biased	492.05	492.54	0.4891
31	30	Unbiased	505.6	505.65	0.0535
33	30	Biased	500.31	500.71	0.4037
34	50	Unbiased	491.69	494.46	2.7678
35	20	Unbiased	497.98	497.9	-0.0819
41	30	Biased	496.9	488.69	-8.2013

Test Statistics (kHz)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	486.31	493.37	499.33	5.6334	486.54	493.51	499.45	5.5734	0.0546	0.13735	0.2326	0.073735
20	492.05	496.85	502.09	3.2999	492.54	496.79	501.37	2.9548	-1.1524	-0.06425	1.2492	0.70763
30	494.42	501.77	510.18	5.1569	488.69	501.26	509.4	6.3635	-8.2013	-0.50573	2.2487	2.8391
50	488.87	496.13	503.88	4.8669	484.87	496.08	503.31	5.7694	-3.9993	-0.05828	2.7678	1.9412

Device Test: 20.45 PF|DCL_48/SYNC/5/5/0/0/5/500kHz//@DUTY_SYNC_EXT_DCL50





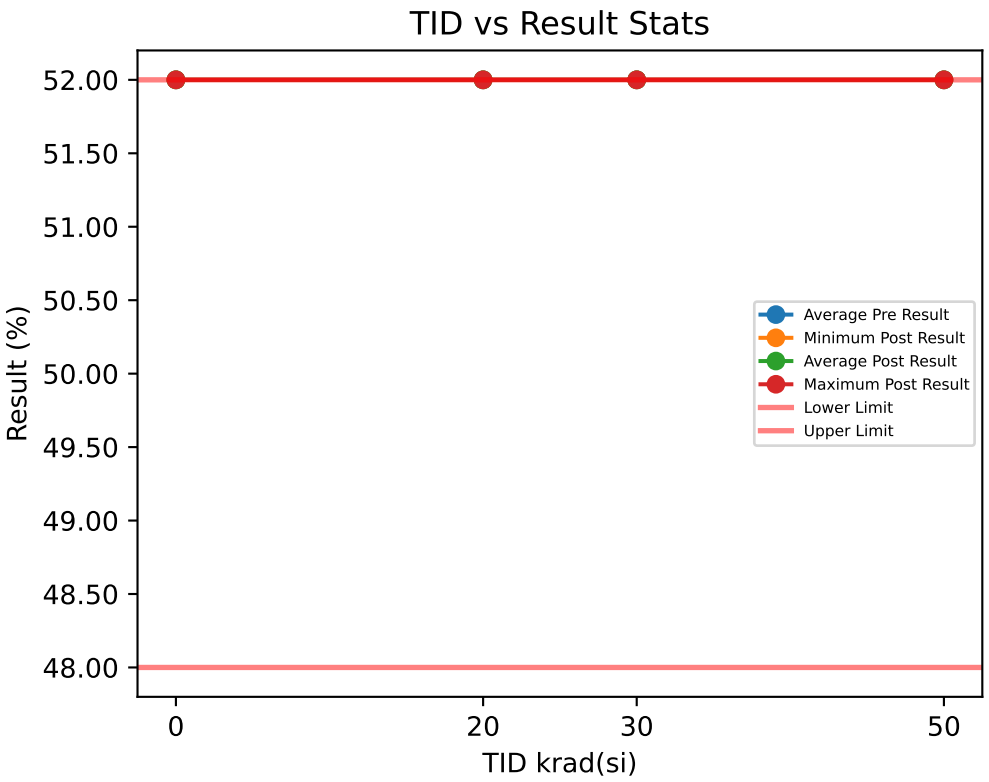
Test Results (Lower Limit = 48.0, Upper Limit = 52.0 (%))

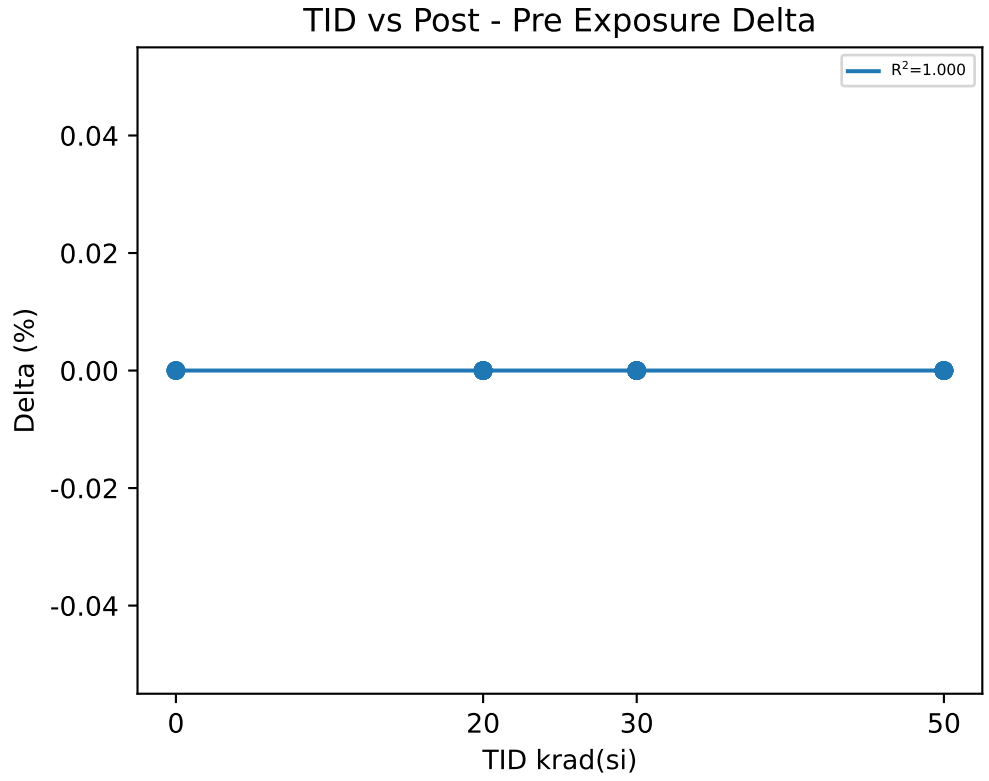
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	48	48	0
2	20	Unbiased	48	48	0
3	50	Biased	48	48	0
4	30	Unbiased	48	48	0
5	50	Unbiased	48	48	0
6	30	Biased	48	48	0
7	50	Biased	48	48	0
8	30	Unbiased	48	48	0
9	20	Unbiased	48	48	0
10	50	Biased	48	48	0
11	30	Biased	48	48	0
12	0	Correlation	48	48	0
13	0	Correlation	48	48	0
14	50	Unbiased	48	48	0
15	20	Biased	48	48	0
16	20	Unbiased	48	48	0
17	20	Biased	48	48	0
18	20	Unbiased	48	48	0
19	20	Biased	48	48	0
20	50	Unbiased	48	48	0
21	0	Correlation	48	48	0
22	50	Unbiased	48	48	0
23	0	Correlation	48	48	0
24	20	Biased	48	48	0
26	50	Biased	48	48	0
27	30	Unbiased	48	48	0
28	30	Biased	48	48	0
29	30	Unbiased	48	48	0
30	20	Biased	48	48	0
31	30	Unbiased	48	48	0
33	30	Biased	48	48	0
34	50	Unbiased	48	48	0
35	20	Unbiased	48	48	0
41	30	Biased	48	48	0

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	48	48	48	0	48	48	48	0	0	0	0	0
20	48	48	48	0	48	48	48	0	0	0	0	0
30	48	48	48	0	48	48	48	0	0	0	0	0
50	48	48	48	0	48	48	48	0	0	0	0	0

Device Test: 20.46 PF|DCL_52/SYNC/5/5/0/0/5/500kHz//@DUTY_SYNC_EXT_DCL50





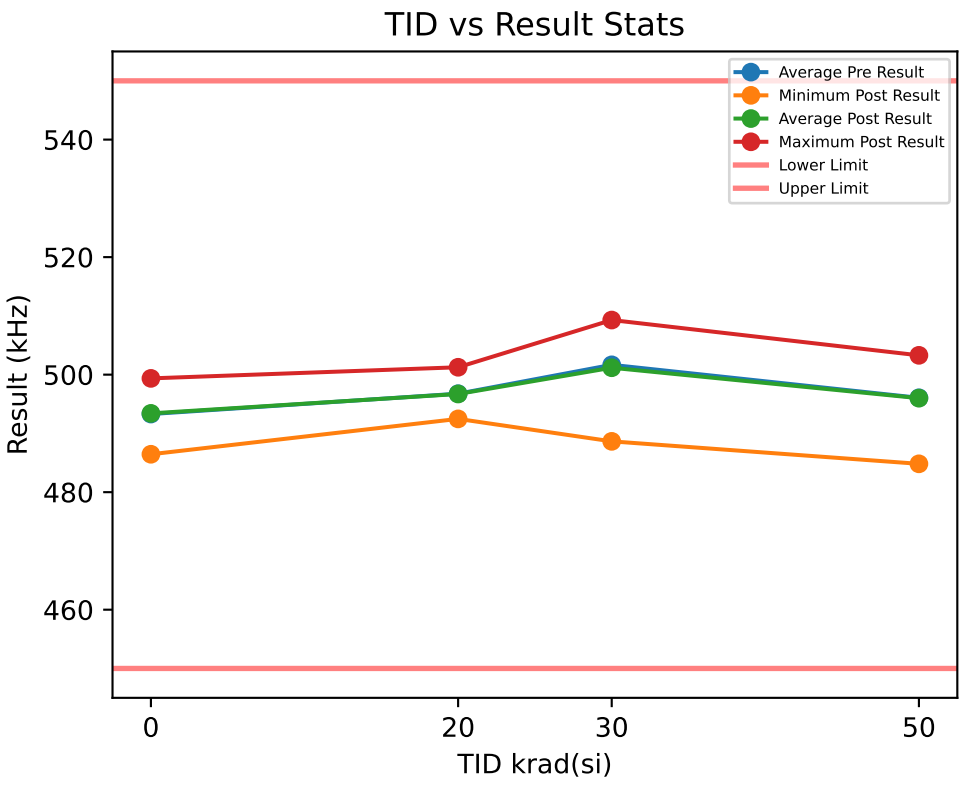
Test Results (Lower Limit = 48.0, Upper Limit = 52.0 (%))

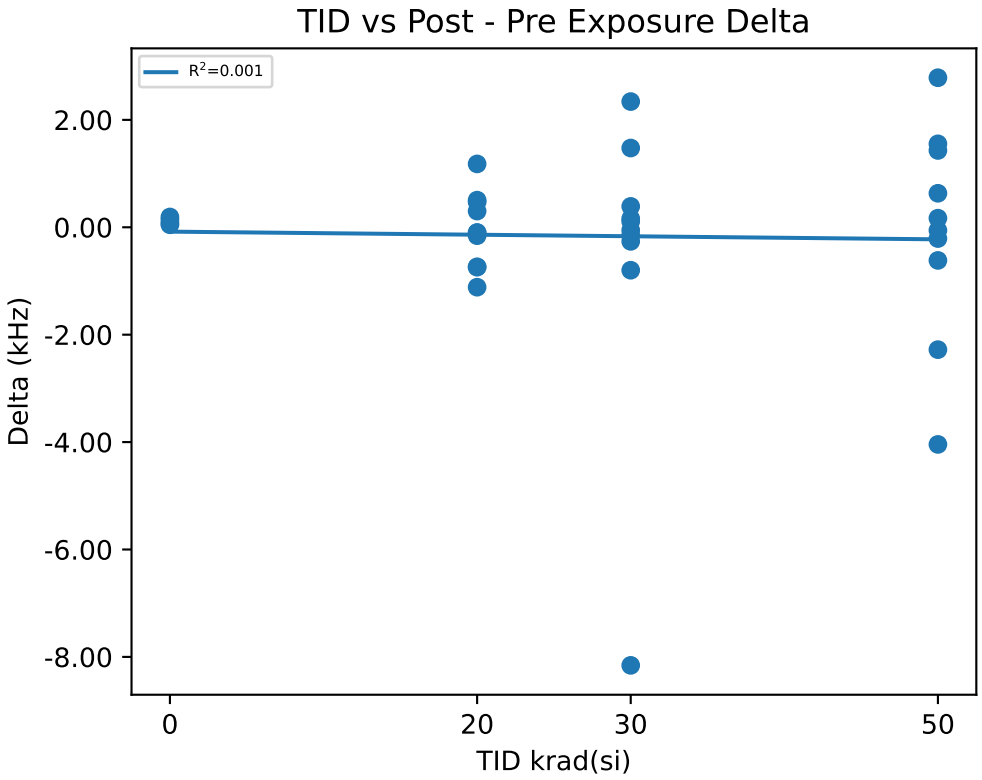
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	52	52	0
2	20	Unbiased	52	52	0
3	50	Biased	52	52	0
4	30	Unbiased	52	52	0
5	50	Unbiased	52	52	0
6	30	Biased	52	52	0
7	50	Biased	52	52	0
8	30	Unbiased	52	52	0
9	20	Unbiased	52	52	0
10	50	Biased	52	52	0
11	30	Biased	52	52	0
12	0	Correlation	52	52	0
13	0	Correlation	52	52	0
14	50	Unbiased	52	52	0
15	20	Biased	52	52	0
16	20	Unbiased	52	52	0
17	20	Biased	52	52	0
18	20	Unbiased	52	52	0
19	20	Biased	52	52	0
20	50	Unbiased	52	52	0
21	0	Correlation	52	52	0
22	50	Unbiased	52	52	0
23	0	Correlation	52	52	0
24	20	Biased	52	52	0
26	50	Biased	52	52	0
27	30	Unbiased	52	52	0
28	30	Biased	52	52	0
29	30	Unbiased	52	52	0
30	20	Biased	52	52	0
31	30	Unbiased	52	52	0
33	30	Biased	52	52	0
34	50	Unbiased	52	52	0
35	20	Unbiased	52	52	0
41	30	Biased	52	52	0

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	52	52	52	0	52	52	52	0	0	0	0	0
20	52	52	52	0	52	52	52	0	0	0	0	0
30	52	52	52	0	52	52	52	0	0	0	0	0
50	52	52	52	0	52	52	52	0	0	0	0	0

Device Test: 20.47 LEVEL|FREQ/RT/12/12/0/0/5/500kHz//@FSW_EXT_RT_C





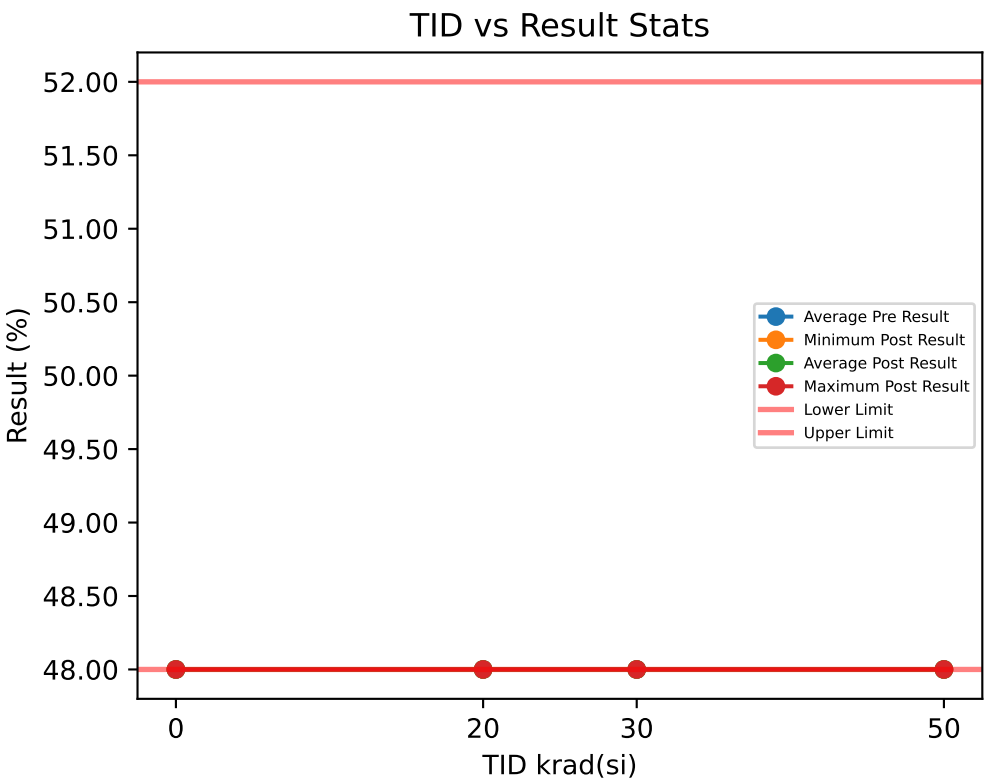
Test Results (Lower Limit = 450.0, Upper Limit = 550.0 (kHz))

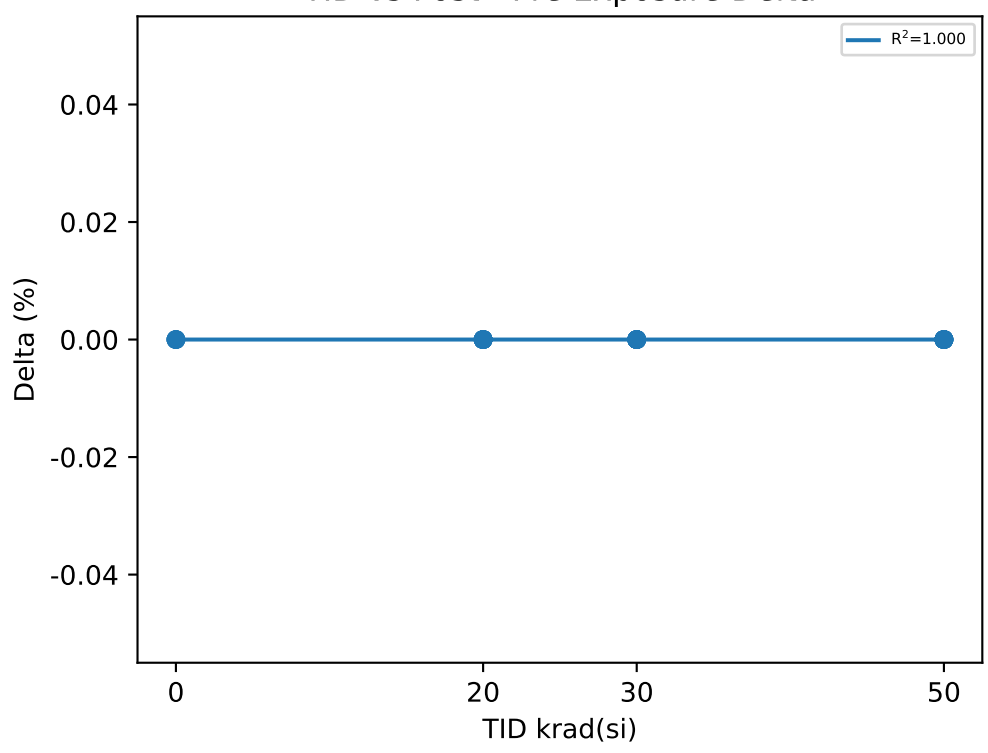
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	491.4	491.2	-0.2099
2	20	Unbiased	498.61	497.87	-0.7369
3	50	Biased	501.16	502.59	1.4305
4	30	Unbiased	504.47	504.32	-0.1496
5	50	Unbiased	488.87	484.82	-4.0433
6	30	Biased	496.41	498.75	2.3407
7	50	Biased	498.09	498.03	-0.0568
8	30	Unbiased	498.51	498.46	-0.0536
9	20	Unbiased	494.02	493.92	-0.097
10	50	Biased	500.88	501.51	0.6331
11	30	Biased	503.82	505.29	1.4758
12	0	Correlation	486.26	486.45	0.1917
13	0	Correlation	491.64	491.78	0.1373
14	50	Unbiased	503.9	503.29	-0.6171
15	20	Biased	495.76	496.26	0.5051
16	20	Unbiased	492.39	493.57	1.1799
17	20	Biased	502	501.26	-0.7421
18	20	Unbiased	496.16	495.04	-1.1157
19	20	Biased	500.13	499.97	-0.1563
20	50	Unbiased	494.95	492.68	-2.2786
21	0	Correlation	495.99	496.03	0.0471
22	50	Unbiased	493.67	493.83	0.1694
23	0	Correlation	499.29	499.36	0.0747
24	20	Biased	498.57	498.87	0.3017
26	50	Biased	496.09	497.64	1.5538
27	30	Unbiased	494.34	494.08	-0.2622
28	30	Biased	506.49	506.65	0.1627
29	30	Unbiased	510.09	509.29	-0.7996
30	20	Biased	492	492.47	0.4698
31	30	Unbiased	505.52	505.62	0.1071
33	30	Biased	500.25	500.64	0.389
34	50	Unbiased	491.6	494.38	2.7846
35	20	Unbiased	497.95	497.85	-0.1035
41	30	Biased	496.8	488.65	-8.1574

Test Statistics (kHz)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	486.26	493.3	499.29	5.6389	486.45	493.41	499.36	5.5798	0.0471	0.1127	0.1917	0.064791
20	492	496.76	502	3.292	492.47	496.71	501.26	2.9292	-1.1157	-0.0495	1.1799	0.69263
30	494.34	501.67	510.09	5.1478	488.65	501.18	509.29	6.3545	-8.1574	-0.49471	2.3407	2.8417
50	488.87	496.06	503.9	4.8894	484.82	496	503.29	5.7742	-4.0433	-0.06343	2.7846	1.9599

Device Test: 20.49 PF|DCL_48/SYNC/12/12/0/0/5/500kHz//@DUTY_SYNC_EXT_DCL50





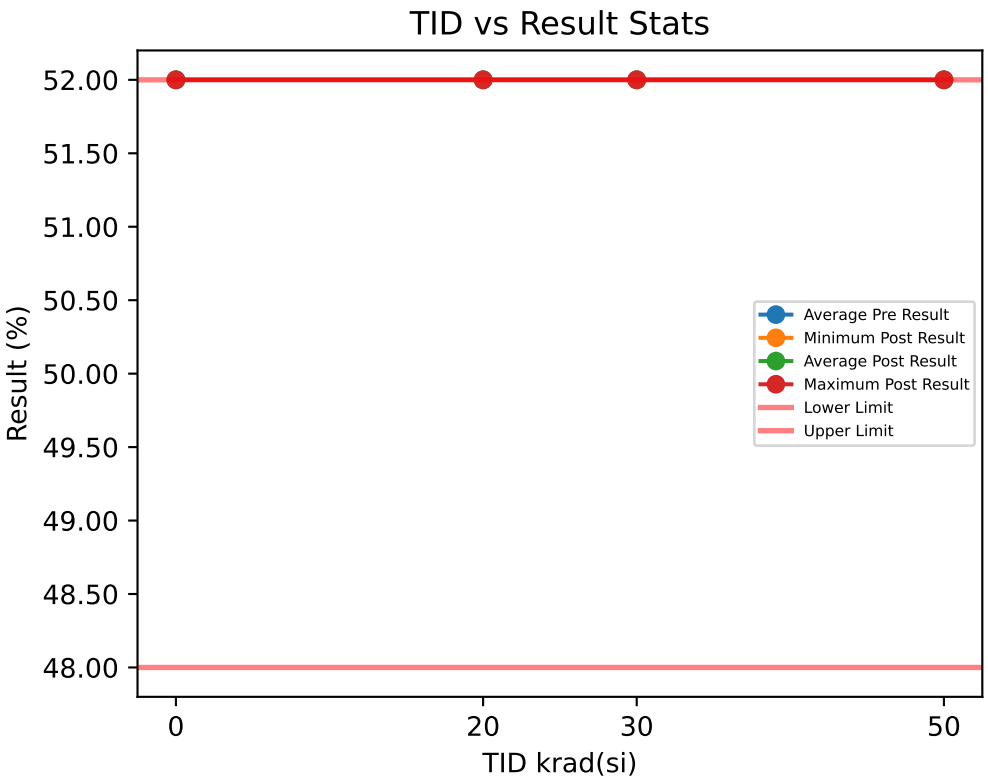
Test Results (Lower Limit = 48.0, Upper Limit = 52.0 (%))

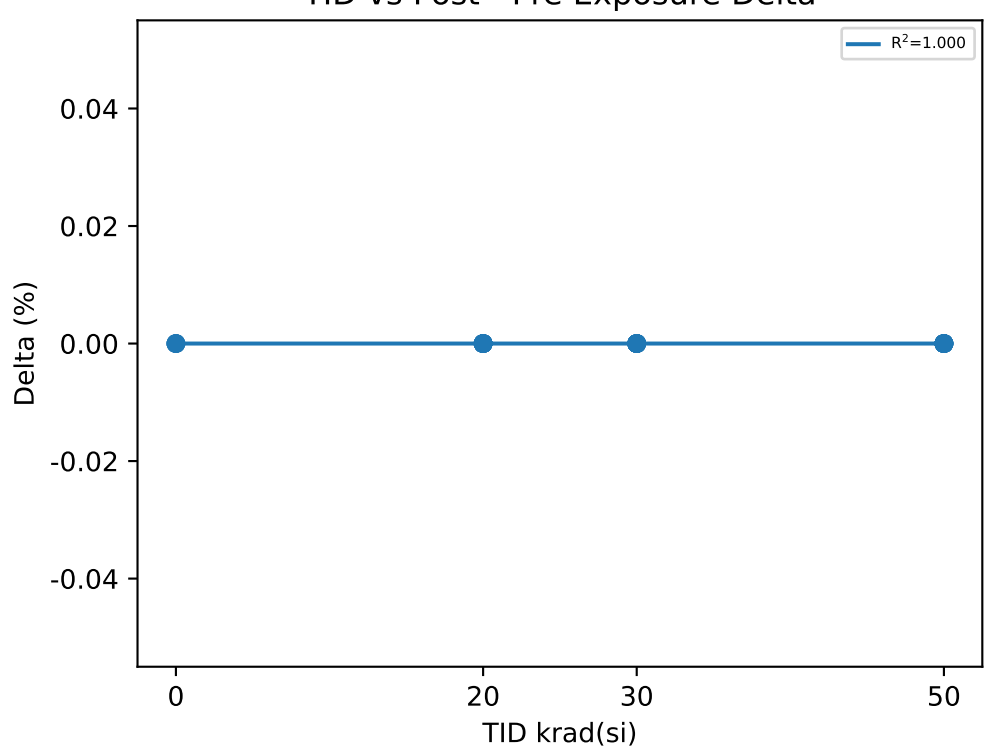
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	48	48	0
2	20	Unbiased	48	48	0
3	50	Biased	48	48	0
4	30	Unbiased	48	48	0
5	50	Unbiased	48	48	0
6	30	Biased	48	48	0
7	50	Biased	48	48	0
8	30	Unbiased	48	48	0
9	20	Unbiased	48	48	0
10	50	Biased	48	48	0
11	30	Biased	48	48	0
12	0	Correlation	48	48	0
13	0	Correlation	48	48	0
14	50	Unbiased	48	48	0
15	20	Biased	48	48	0
16	20	Unbiased	48	48	0
17	20	Biased	48	48	0
18	20	Unbiased	48	48	0
19	20	Biased	48	48	0
20	50	Unbiased	48	48	0
21	0	Correlation	48	48	0
22	50	Unbiased	48	48	0
23	0	Correlation	48	48	0
24	20	Biased	48	48	0
26	50	Biased	48	48	0
27	30	Unbiased	48	48	0
28	30	Biased	48	48	0
29	30	Unbiased	48	48	0
30	20	Biased	48	48	0
31	30	Unbiased	48	48	0
33	30	Biased	48	48	0
34	50	Unbiased	48	48	0
35	20	Unbiased	48	48	0
41	30	Biased	48	48	0

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	48	48	48	0	48	48	48	0	0	0	0	0
20	48	48	48	0	48	48	48	0	0	0	0	0
30	48	48	48	0	48	48	48	0	0	0	0	0
50	48	48	48	0	48	48	48	0	0	0	0	0

Device Test: 20.50 PF|DCL_52/SYNC/12/12/0/0/5/500kHz//@DUTY_SYNC_EXT_DCL50





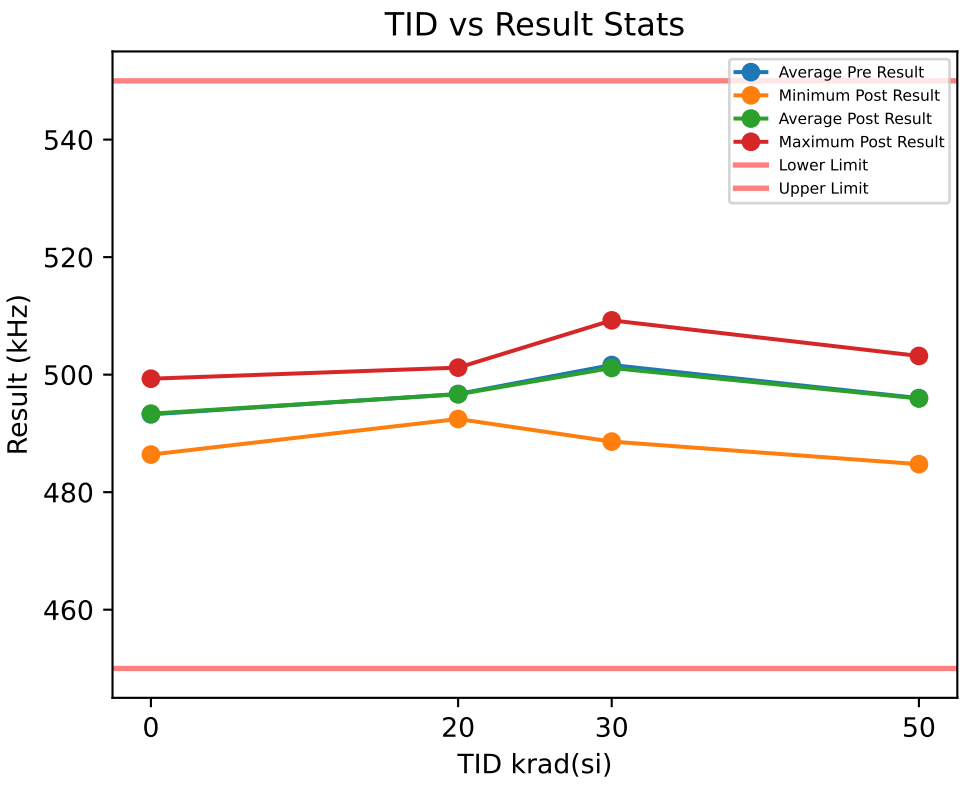
Test Results (Lower Limit = 48.0, Upper Limit = 52.0 (%))

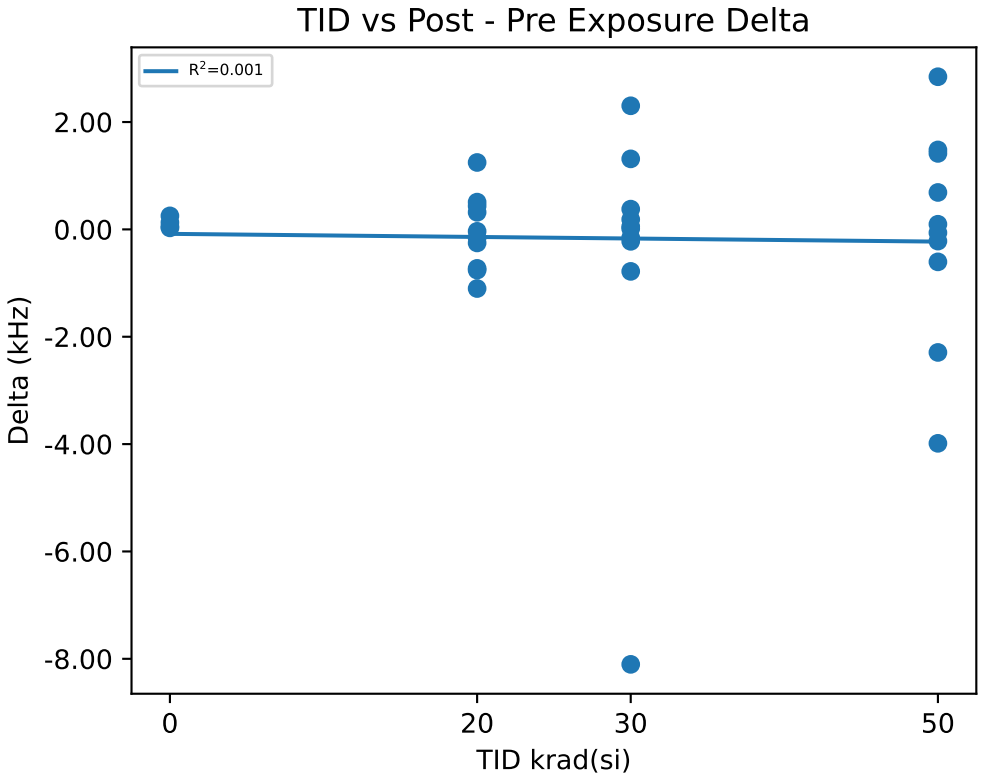
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	52	52	0
2	20	Unbiased	52	52	0
3	50	Biased	52	52	0
4	30	Unbiased	52	52	0
5	50	Unbiased	52	52	0
6	30	Biased	52	52	0
7	50	Biased	52	52	0
8	30	Unbiased	52	52	0
9	20	Unbiased	52	52	0
10	50	Biased	52	52	0
11	30	Biased	52	52	0
12	0	Correlation	52	52	0
13	0	Correlation	52	52	0
14	50	Unbiased	52	52	0
15	20	Biased	52	52	0
16	20	Unbiased	52	52	0
17	20	Biased	52	52	0
18	20	Unbiased	52	52	0
19	20	Biased	52	52	0
20	50	Unbiased	52	52	0
21	0	Correlation	52	52	0
22	50	Unbiased	52	52	0
23	0	Correlation	52	52	0
24	20	Biased	52	52	0
26	50	Biased	52	52	0
27	30	Unbiased	52	52	0
28	30	Biased	52	52	0
29	30	Unbiased	52	52	0
30	20	Biased	52	52	0
31	30	Unbiased	52	52	0
33	30	Biased	52	52	0
34	50	Unbiased	52	52	0
35	20	Unbiased	52	52	0
41	30	Biased	52	52	0

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	52	52	52	0	52	52	52	0	0	0	0	0
20	52	52	52	0	52	52	52	0	0	0	0	0
30	52	52	52	0	52	52	52	0	0	0	0	0
50	52	52	52	0	52	52	52	0	0	0	0	0

Device Test: 20.51 LEVEL|FREQ/RT/14/14/0/0/5/500kHz//@FSW_EXT_RT_C





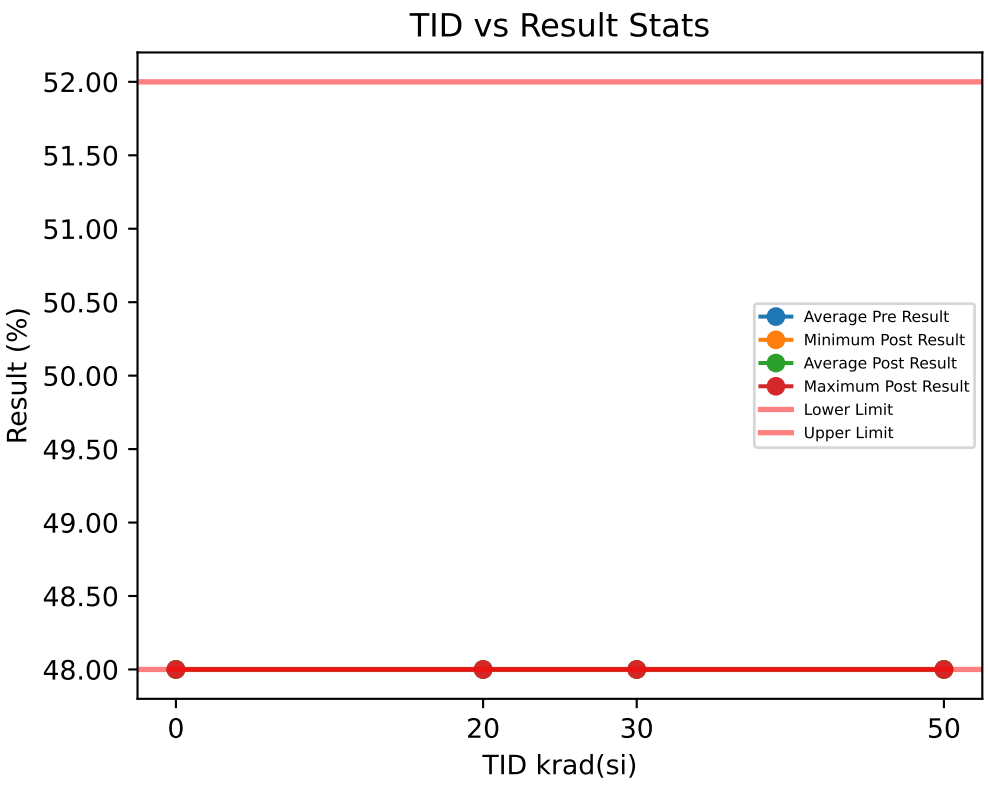
Test Results (Lower Limit = 450.0, Upper Limit = 550.0 (kHz))

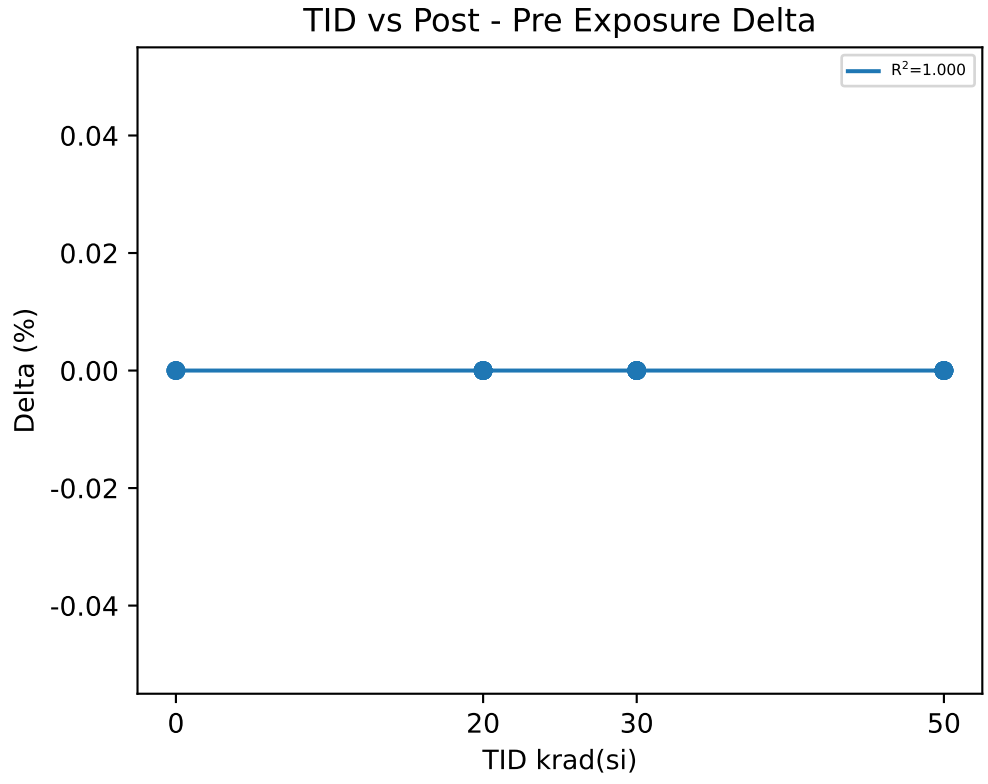
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	491.42	491.2	-0.2181
2	20	Unbiased	498.55	497.79	-0.7585
3	50	Biased	501.11	502.52	1.4155
4	30	Unbiased	504.45	504.3	-0.1533
5	50	Unbiased	488.75	484.76	-3.9855
6	30	Biased	496.4	498.7	2.3028
7	50	Biased	498.08	498.01	-0.0624
8	30	Unbiased	498.43	498.44	0.0135
9	20	Unbiased	494.12	493.87	-0.2523
10	50	Biased	500.8	501.49	0.6882
11	30	Biased	503.94	505.25	1.3138
12	0	Correlation	486.14	486.4	0.2518
13	0	Correlation	491.6	491.73	0.1288
14	50	Unbiased	503.79	503.18	-0.6049
15	20	Biased	495.77	496.21	0.4363
16	20	Unbiased	492.3	493.54	1.2468
17	20	Biased	501.92	501.19	-0.7261
18	20	Unbiased	496.07	494.97	-1.1016
19	20	Biased	500.06	499.9	-0.1547
20	50	Unbiased	494.9	492.61	-2.2922
21	0	Correlation	495.94	495.99	0.0525
22	50	Unbiased	493.63	493.73	0.0958
23	0	Correlation	499.28	499.31	0.0284
24	20	Biased	498.52	498.84	0.3187
26	50	Biased	496.07	497.55	1.4802
27	30	Unbiased	494.28	494.05	-0.2225
28	30	Biased	506.45	506.64	0.1856
29	30	Unbiased	510.02	509.24	-0.7823
30	20	Biased	491.94	492.45	0.508
31	30	Unbiased	505.49	505.54	0.0522
33	30	Biased	500.21	500.59	0.3774
34	50	Unbiased	491.53	494.37	2.8439
35	20	Unbiased	497.86	497.82	-0.0362
41	30	Biased	496.71	488.61	-8.1033

Test Statistics (kHz)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	486.14	493.24	499.28	5.6796	486.4	493.36	499.31	5.5807	0.0284	0.11538	0.2518	0.10052
20	491.94	496.71	501.92	3.2748	492.45	496.66	501.19	2.9199	-1.1016	-0.05196	1.2468	0.70573
30	494.28	501.64	510.02	5.1616	488.61	501.14	509.24	6.3498	-8.1033	-0.50161	2.3028	2.8095
50	488.75	496.01	503.79	4.8814	484.76	495.94	503.18	5.7664	-3.9855	-0.06395	2.8439	1.9516

Device Test: 20.53 PF|DCL_48/SYNC/14/14/0/0/5/500kHz//@DUTY_SYNC_EXT_DCL50





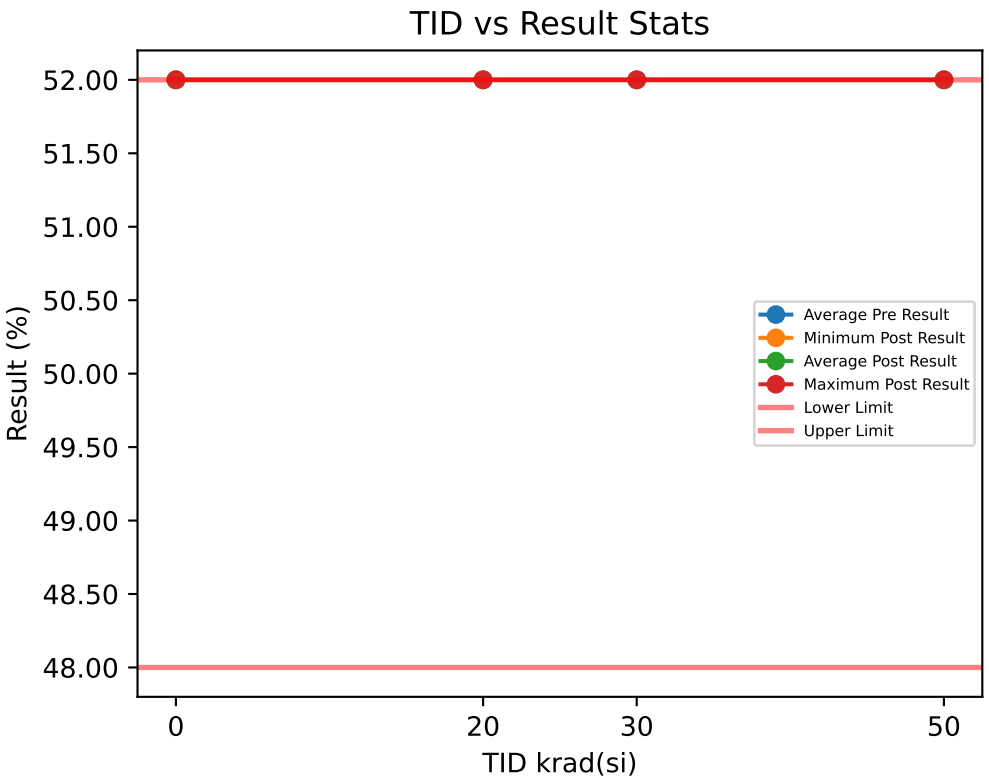
Test Results (Lower Limit = 48.0, Upper Limit = 52.0 (%))

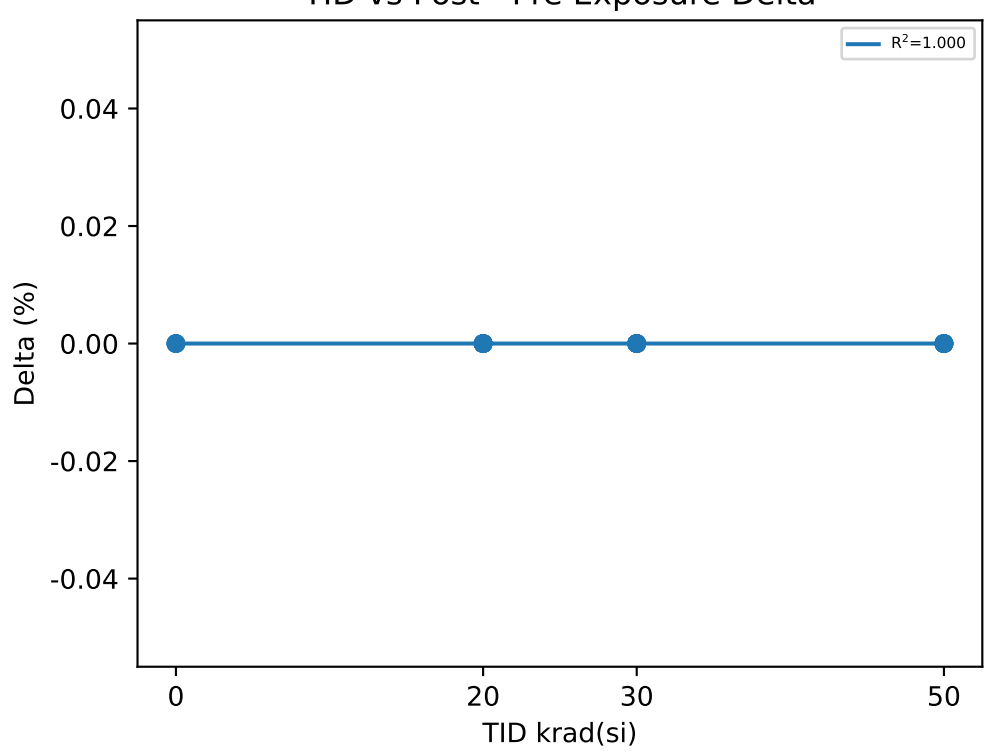
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	48	48	0
2	20	Unbiased	48	48	0
3	50	Biased	48	48	0
4	30	Unbiased	48	48	0
5	50	Unbiased	48	48	0
6	30	Biased	48	48	0
7	50	Biased	48	48	0
8	30	Unbiased	48	48	0
9	20	Unbiased	48	48	0
10	50	Biased	48	48	0
11	30	Biased	48	48	0
12	0	Correlation	48	48	0
13	0	Correlation	48	48	0
14	50	Unbiased	48	48	0
15	20	Biased	48	48	0
16	20	Unbiased	48	48	0
17	20	Biased	48	48	0
18	20	Unbiased	48	48	0
19	20	Biased	48	48	0
20	50	Unbiased	48	48	0
21	0	Correlation	48	48	0
22	50	Unbiased	48	48	0
23	0	Correlation	48	48	0
24	20	Biased	48	48	0
26	50	Biased	48	48	0
27	30	Unbiased	48	48	0
28	30	Biased	48	48	0
29	30	Unbiased	48	48	0
30	20	Biased	48	48	0
31	30	Unbiased	48	48	0
33	30	Biased	48	48	0
34	50	Unbiased	48	48	0
35	20	Unbiased	48	48	0
41	30	Biased	48	48	0

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	48	48	48	0	48	48	48	0	0	0	0	0
20	48	48	48	0	48	48	48	0	0	0	0	0
30	48	48	48	0	48	48	48	0	0	0	0	0
50	48	48	48	0	48	48	48	0	0	0	0	0

Device Test: 20.54 PF|DCL_52/SYNC/14/14/0/0/5/500kHz//@DUTY_SYNC_EXT_DCL50





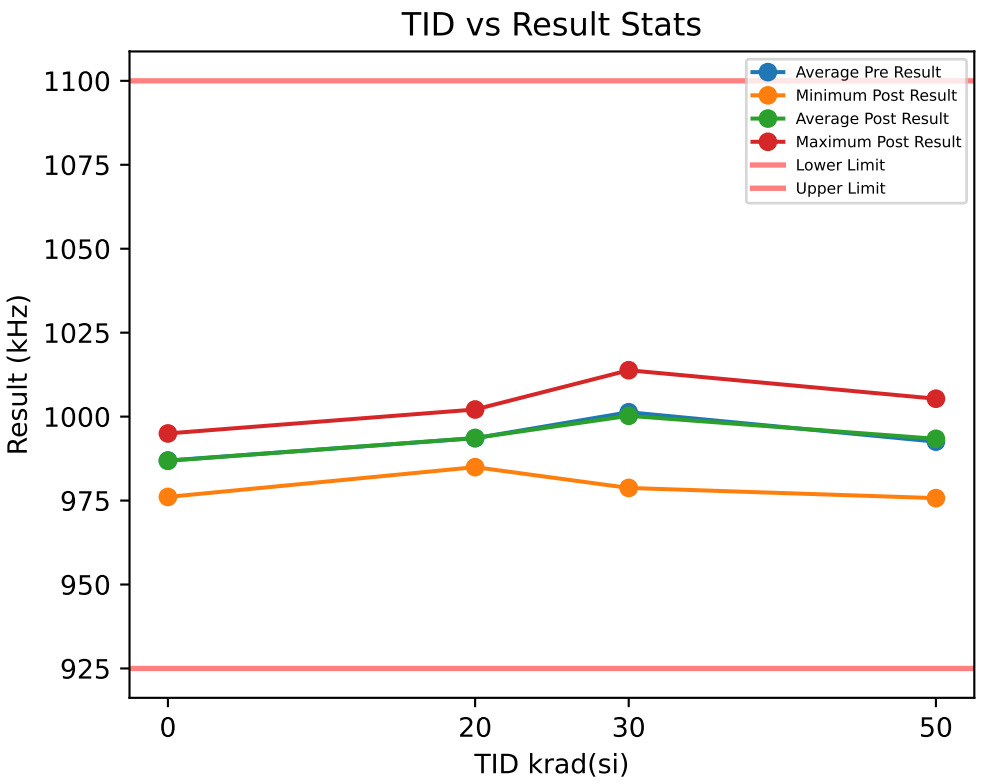
Test Results (Lower Limit = 48.0, Upper Limit = 52.0 (%))

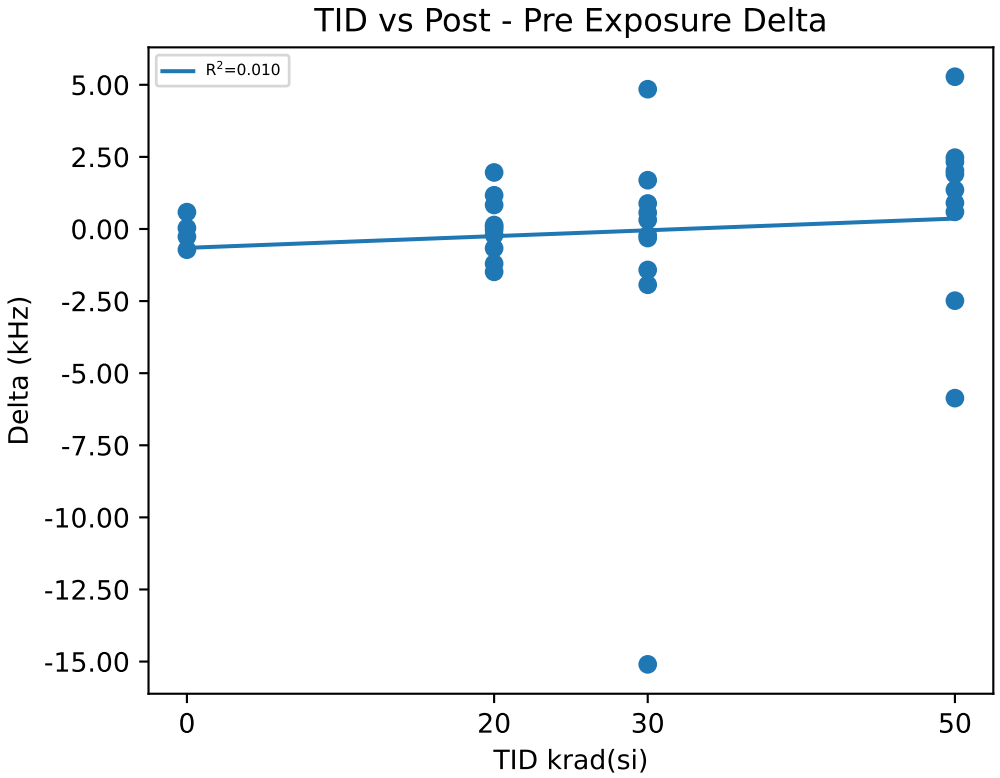
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	52	52	0
2	20	Unbiased	52	52	0
3	50	Biased	52	52	0
4	30	Unbiased	52	52	0
5	50	Unbiased	52	52	0
6	30	Biased	52	52	0
7	50	Biased	52	52	0
8	30	Unbiased	52	52	0
9	20	Unbiased	52	52	0
10	50	Biased	52	52	0
11	30	Biased	52	52	0
12	0	Correlation	52	52	0
13	0	Correlation	52	52	0
14	50	Unbiased	52	52	0
15	20	Biased	52	52	0
16	20	Unbiased	52	52	0
17	20	Biased	52	52	0
18	20	Unbiased	52	52	0
19	20	Biased	52	52	0
20	50	Unbiased	52	52	0
21	0	Correlation	52	52	0
22	50	Unbiased	52	52	0
23	0	Correlation	52	52	0
24	20	Biased	52	52	0
26	50	Biased	52	52	0
27	30	Unbiased	52	52	0
28	30	Biased	52	52	0
29	30	Unbiased	52	52	0
30	20	Biased	52	52	0
31	30	Unbiased	52	52	0
33	30	Biased	52	52	0
34	50	Unbiased	52	52	0
35	20	Unbiased	52	52	0
41	30	Biased	52	52	0

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	52	52	52	0	52	52	52	0	0	0	0	0
20	52	52	52	0	52	52	52	0	0	0	0	0
30	52	52	52	0	52	52	52	0	0	0	0	0
50	52	52	52	0	52	52	52	0	0	0	0	0

Device Test: 20.55 LEVEL|FREQ/RT/4.5/4.5/0/0/4.5/1MHz//@FSW_EXT_RT_D





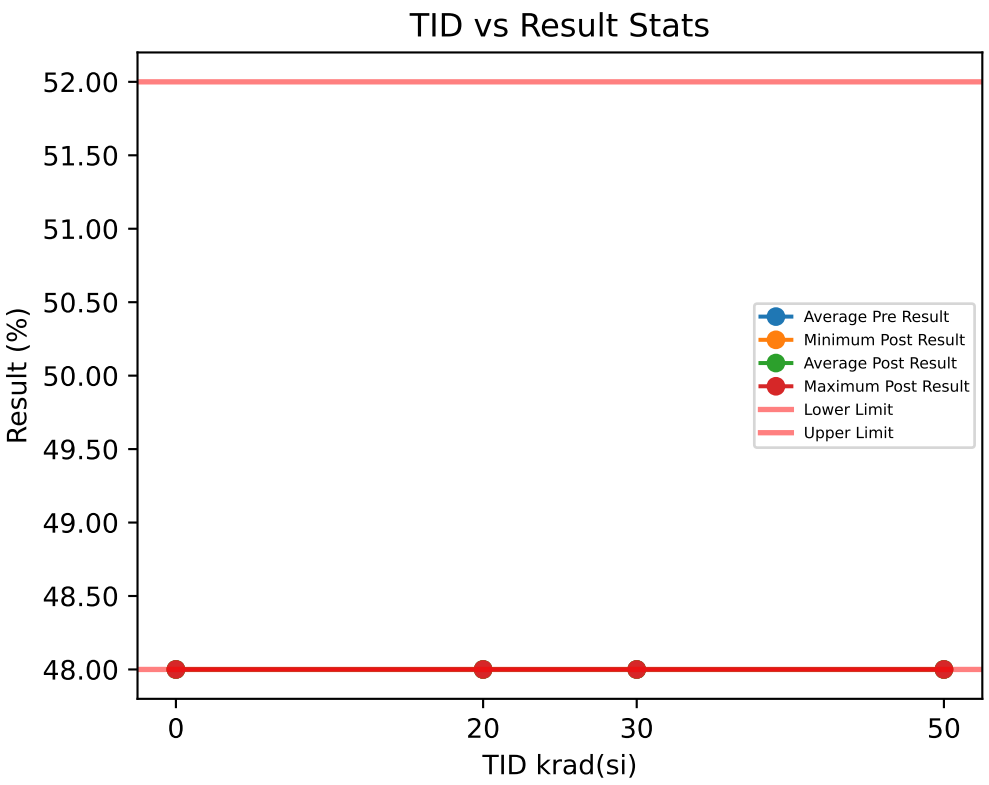
Test Results (Lower Limit = 925.0, Upper Limit = 1100.0 (kHz))

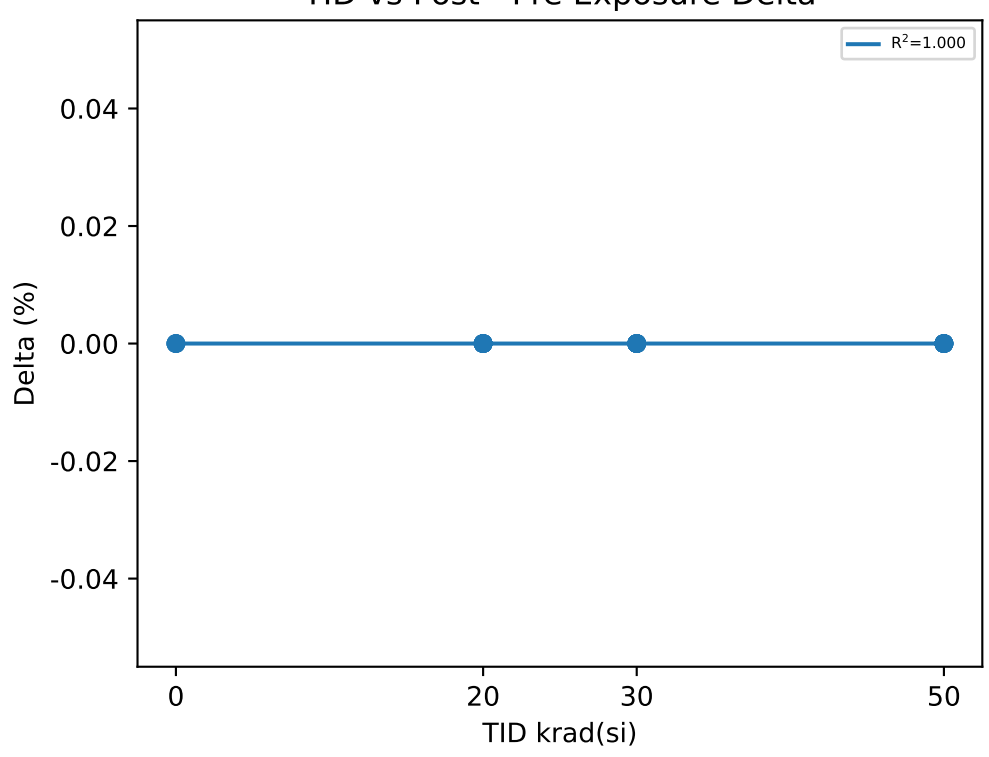
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	985.22	986.13	0.9072
2	20	Unbiased	996.65	996.44	-0.2109
3	50	Biased	1003.1	1005.2	2.023
4	30	Unbiased	1007.6	1007.3	-0.218
5	50	Unbiased	981.59	975.72	-5.8652
6	30	Biased	992.81	997.65	4.8474
7	50	Biased	995.52	996.88	1.3568
8	30	Unbiased	995.35	993.42	-1.9342
9	20	Unbiased	989.84	991	1.1689
10	50	Biased	999	1000.9	1.9032
11	30	Biased	1005.9	1007.6	1.6914
12	0	Correlation	976.05	976.08	0.0331
13	0	Correlation	982.65	983.24	0.5847
14	50	Unbiased	1004.7	1005.3	0.594
15	20	Biased	993.31	993.29	-0.0239
16	20	Unbiased	985.67	986.51	0.8322
17	20	Biased	1000.9	999.39	-1.4865
18	20	Unbiased	990.77	989.56	-1.2017
19	20	Biased	1002	1002.1	0.1375
20	50	Unbiased	990.13	987.65	-2.4856
21	0	Correlation	993.75	993.03	-0.7184
22	50	Unbiased	987.54	989.87	2.3284
23	0	Correlation	995.26	994.99	-0.2667
24	20	Biased	998.31	997.64	-0.669
26	50	Biased	991.73	994.2	2.4734
27	30	Unbiased	989.97	990.29	0.3155
28	30	Biased	1006.9	1007.8	0.8845
29	30	Unbiased	1015.2	1013.8	-1.4206
30	20	Biased	982.99	984.95	1.9602
31	30	Unbiased	1006.8	1006.5	-0.3144
33	30	Biased	998.73	999.29	0.5642
34	50	Unbiased	986.84	992.12	5.2794
35	20	Unbiased	995.39	995.47	0.0773
41	30	Biased	993.86	978.76	-15.097

Test Statistics (kHz)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	976.05	986.93	995.26	9.1749	976.08	986.83	994.99	8.8218	-0.7184	-0.091825	0.5847	0.54665
20	982.99	993.58	1002	6.2851	984.95	993.64	1002.1	5.5996	-1.4865	0.05841	1.9602	1.0561
30	989.97	1001.3	1015.2	8.2573	978.76	1000.2	1013.8	10.535	-15.097	-1.0681	4.8474	5.2701
50	981.59	992.54	1004.7	7.8089	975.72	993.4	1005.3	9.2007	-5.8652	0.85146	5.2794	3.0454

Device Test: 20.57 PF|DCL_48/SYNC/4.5/4.5/0/0/4.5/1MHz//@DUTY_SYNC_EXT_DCL50





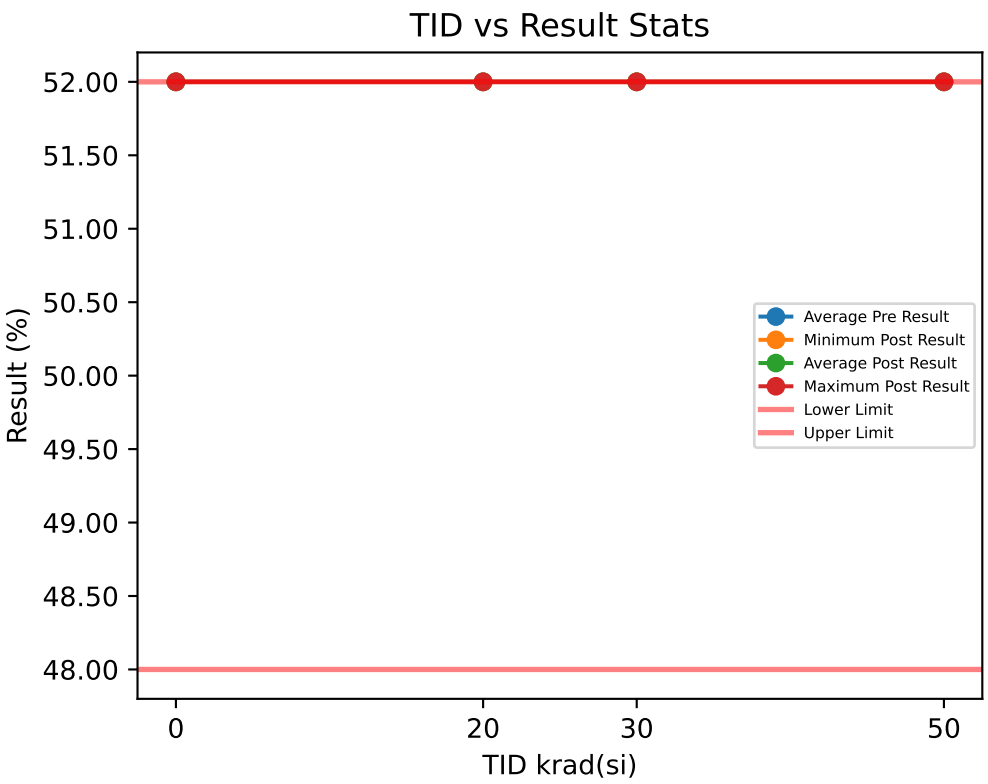
Test Results (Lower Limit = 48.0, Upper Limit = 52.0 (%))

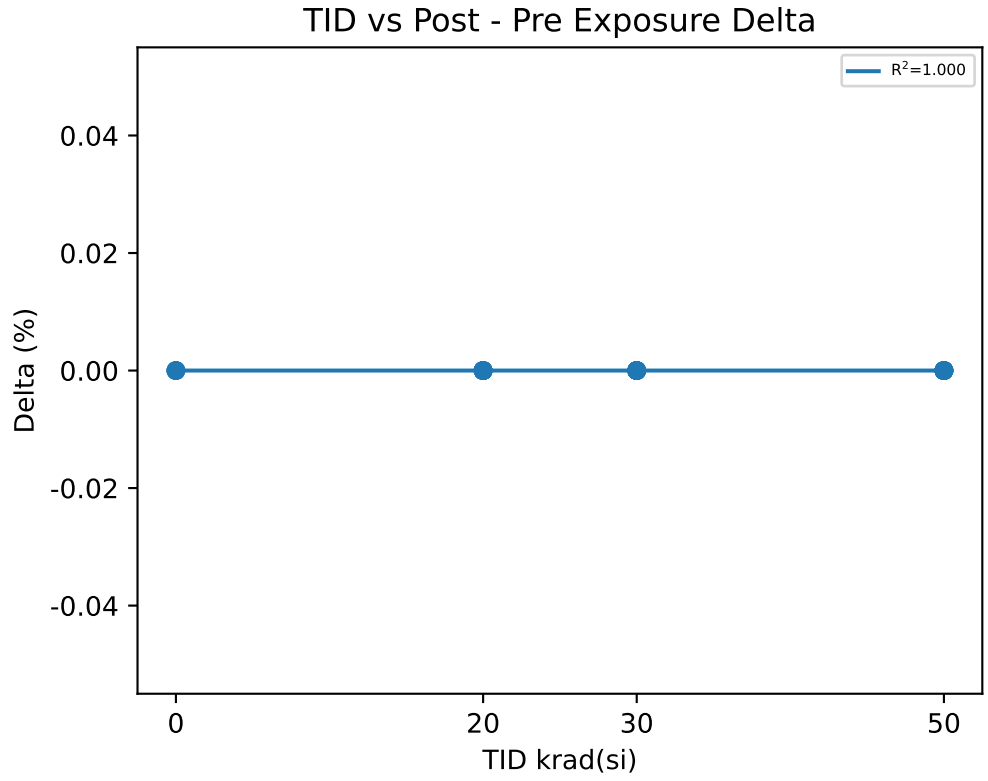
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	48	48	0
2	20	Unbiased	48	48	0
3	50	Biased	48	48	0
4	30	Unbiased	48	48	0
5	50	Unbiased	48	48	0
6	30	Biased	48	48	0
7	50	Biased	48	48	0
8	30	Unbiased	48	48	0
9	20	Unbiased	48	48	0
10	50	Biased	48	48	0
11	30	Biased	48	48	0
12	0	Correlation	48	48	0
13	0	Correlation	48	48	0
14	50	Unbiased	48	48	0
15	20	Biased	48	48	0
16	20	Unbiased	48	48	0
17	20	Biased	48	48	0
18	20	Unbiased	48	48	0
19	20	Biased	48	48	0
20	50	Unbiased	48	48	0
21	0	Correlation	48	48	0
22	50	Unbiased	48	48	0
23	0	Correlation	48	48	0
24	20	Biased	48	48	0
26	50	Biased	48	48	0
27	30	Unbiased	48	48	0
28	30	Biased	48	48	0
29	30	Unbiased	48	48	0
30	20	Biased	48	48	0
31	30	Unbiased	48	48	0
33	30	Biased	48	48	0
34	50	Unbiased	48	48	0
35	20	Unbiased	48	48	0
41	30	Biased	48	48	0

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	48	48	48	0	48	48	48	0	0	0	0	0
20	48	48	48	0	48	48	48	0	0	0	0	0
30	48	48	48	0	48	48	48	0	0	0	0	0
50	48	48	48	0	48	48	48	0	0	0	0	0

Device Test: 20.58 PF|DCL_52/SYNC/4.5/4.5/0/0/4.5/1MHz//@DUTY_SYNC_EXT_DCL50





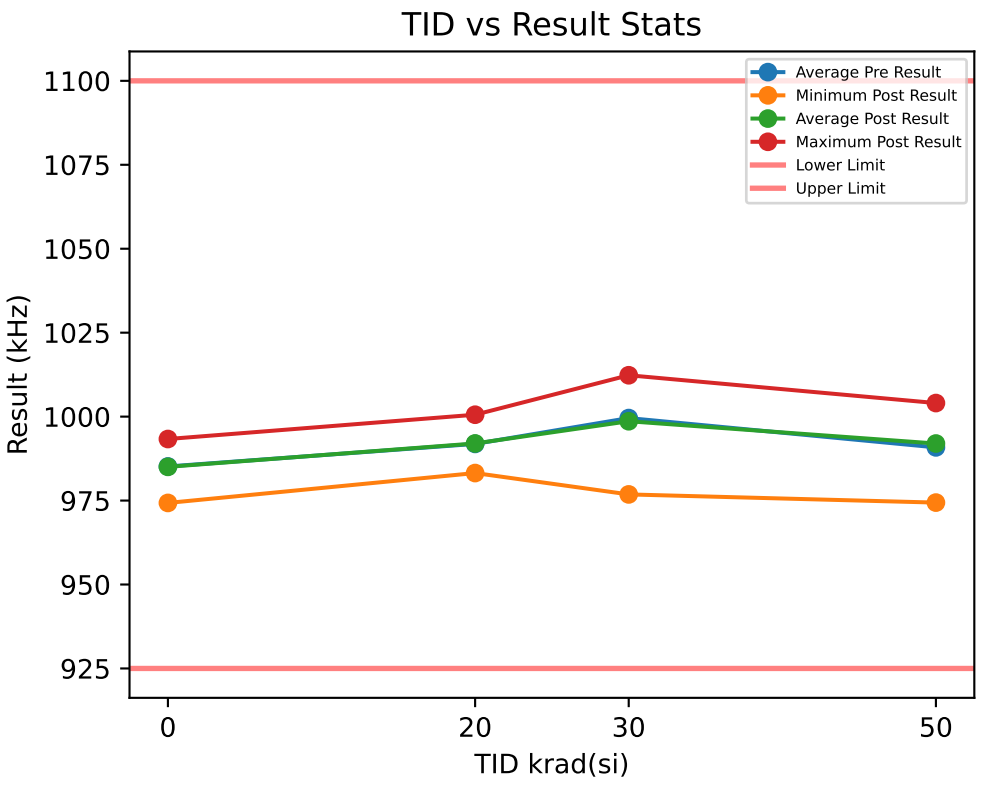
Test Results (Lower Limit = 48.0, Upper Limit = 52.0 (%))

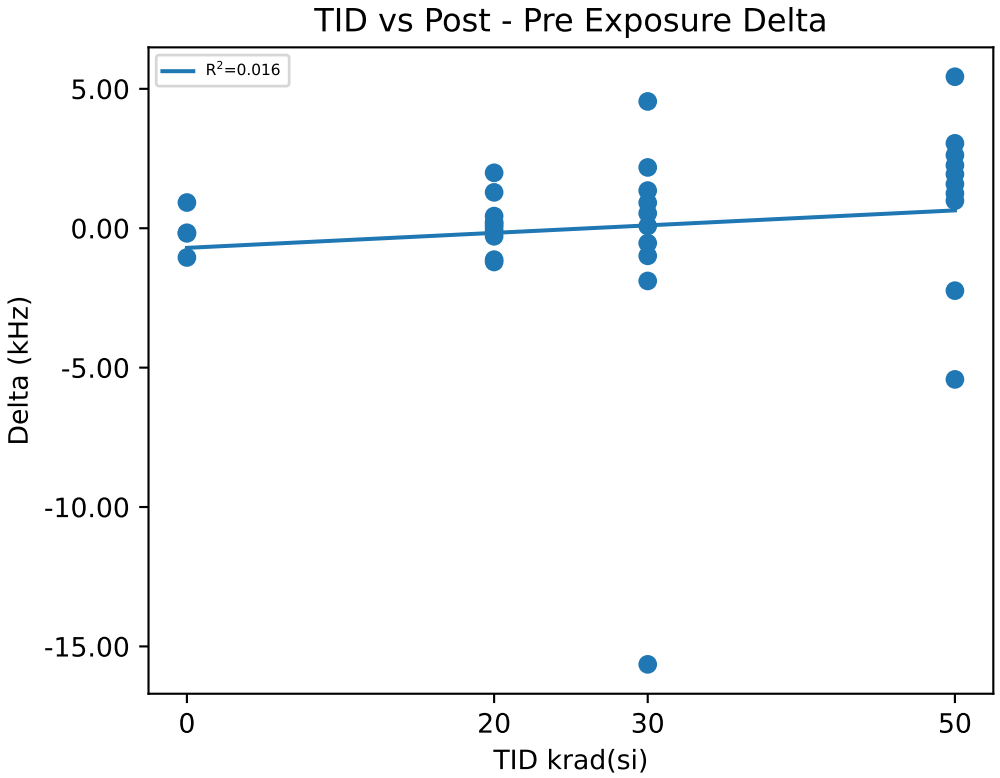
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	52	52	0
2	20	Unbiased	52	52	0
3	50	Biased	52	52	0
4	30	Unbiased	52	52	0
5	50	Unbiased	52	52	0
6	30	Biased	52	52	0
7	50	Biased	52	52	0
8	30	Unbiased	52	52	0
9	20	Unbiased	52	52	0
10	50	Biased	52	52	0
11	30	Biased	52	52	0
12	0	Correlation	52	52	0
13	0	Correlation	52	52	0
14	50	Unbiased	52	52	0
15	20	Biased	52	52	0
16	20	Unbiased	52	52	0
17	20	Biased	52	52	0
18	20	Unbiased	52	52	0
19	20	Biased	52	52	0
20	50	Unbiased	52	52	0
21	0	Correlation	52	52	0
22	50	Unbiased	52	52	0
23	0	Correlation	52	52	0
24	20	Biased	52	52	0
26	50	Biased	52	52	0
27	30	Unbiased	52	52	0
28	30	Biased	52	52	0
29	30	Unbiased	52	52	0
30	20	Biased	52	52	0
31	30	Unbiased	52	52	0
33	30	Biased	52	52	0
34	50	Unbiased	52	52	0
35	20	Unbiased	52	52	0
41	30	Biased	52	52	0

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	52	52	52	0	52	52	52	0	0	0	0	0
20	52	52	52	0	52	52	52	0	0	0	0	0
30	52	52	52	0	52	52	52	0	0	0	0	0
50	52	52	52	0	52	52	52	0	0	0	0	0

Device Test: 20.59 LEVEL|FREQ/RT/5/5/0/0/5/1MHz//@FSW_EXT_RT_D





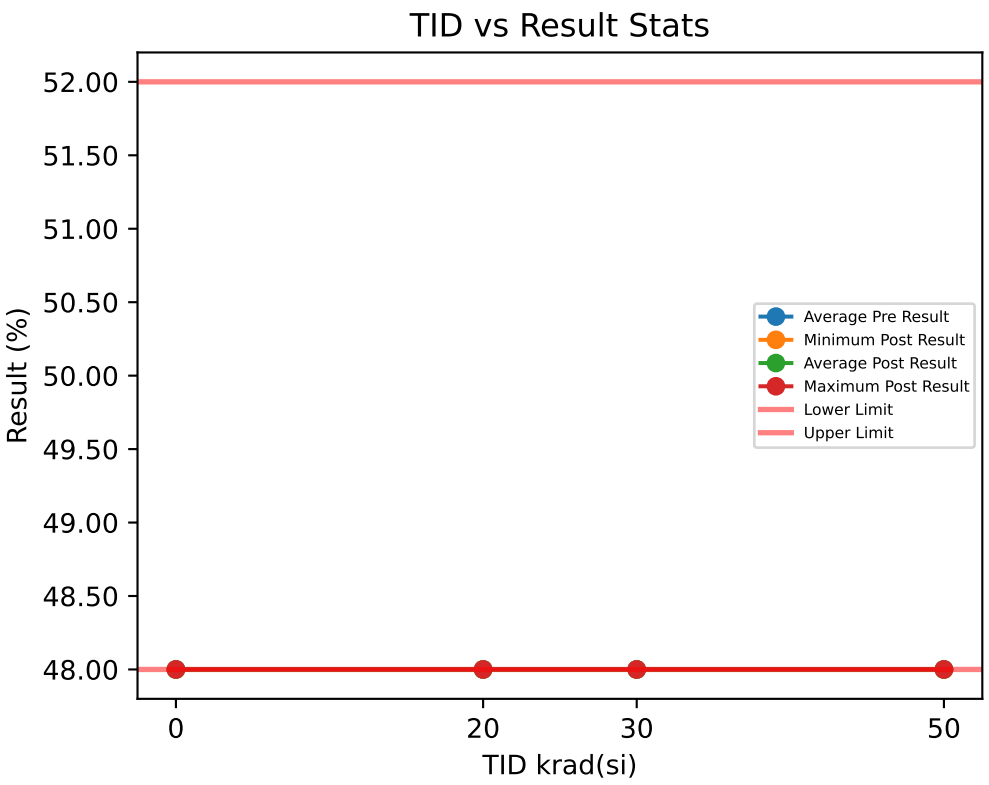
Test Results (Lower Limit = 925.0, Upper Limit = 1100.0 (kHz))

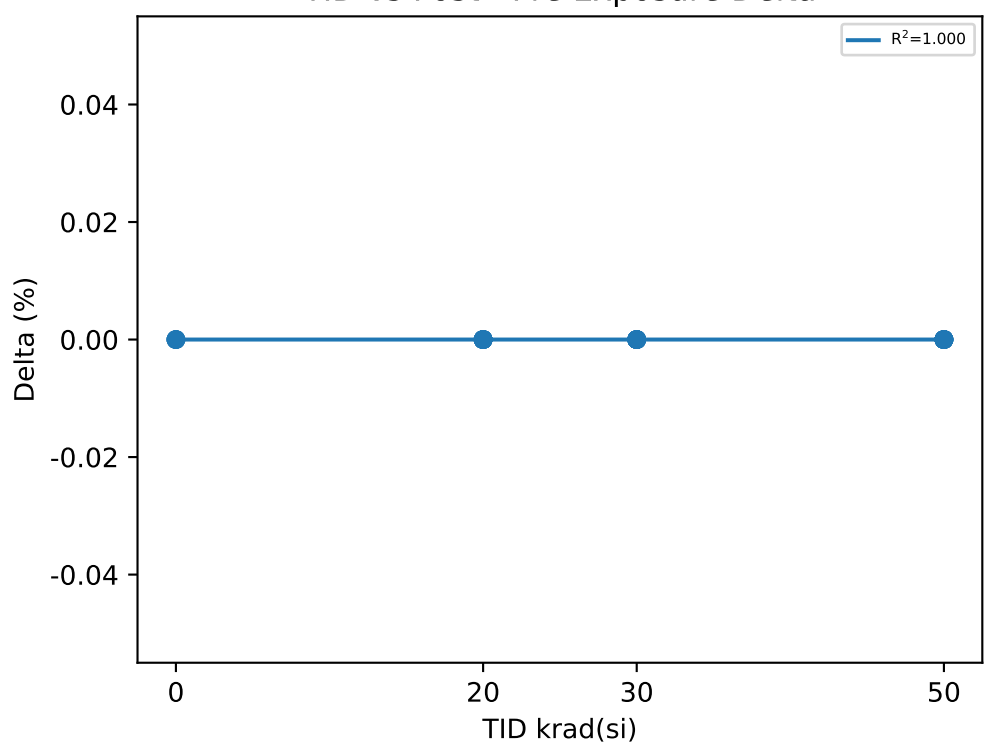
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	983.5	984.75	1.25
2	20	Unbiased	995.04	994.95	-0.0938
3	50	Biased	1001.3	1003.5	2.2577
4	30	Unbiased	1005.9	1006	0.0797
5	50	Unbiased	979.82	974.4	-5.4223
6	30	Biased	991.24	995.79	4.5481
7	50	Biased	993.73	995.31	1.5818
8	30	Unbiased	993.6	991.71	-1.891
9	20	Unbiased	987.93	989.22	1.2866
10	50	Biased	997.35	999.29	1.938
11	30	Biased	1003.9	1006.1	2.1807
12	0	Correlation	974.48	974.3	-0.183
13	0	Correlation	980.48	981.4	0.9222
14	50	Unbiased	1003.1	1004	0.9869
15	20	Biased	991.48	991.52	0.0427
16	20	Unbiased	984.45	984.88	0.4352
17	20	Biased	999.03	997.82	-1.2104
18	20	Unbiased	989.06	987.94	-1.1271
19	20	Biased	1000.4	1000.6	0.1506
20	50	Unbiased	988.58	986.34	-2.2391
21	0	Correlation	992.18	991.13	-1.0493
22	50	Unbiased	985.87	988.5	2.6213
23	0	Correlation	993.49	993.33	-0.1627
24	20	Biased	996.39	996.11	-0.289
26	50	Biased	989.86	992.9	3.0454
27	30	Unbiased	988.09	988.62	0.5357
28	30	Biased	1005.1	1006.4	1.3506
29	30	Unbiased	1013.3	1012.3	-0.9901
30	20	Biased	981.21	983.2	1.9879
31	30	Unbiased	1005	1004.5	-0.5348
33	30	Biased	997.08	998	0.9155
34	50	Unbiased	985.41	990.84	5.4339
35	20	Unbiased	993.7	993.92	0.2215
41	30	Biased	992.48	976.83	-15.644

Test Statistics (kHz)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	974.48	985.16	993.49	9.2158	974.3	985.04	993.33	8.8425	-1.0493	-0.1182	0.9222	0.80737
20	981.21	991.87	1000.4	6.241	983.2	992.01	1000.6	5.6684	-1.2104	0.14042	1.9879	0.97186
30	988.09	999.57	1013.3	8.1701	976.83	998.62	1012.3	10.664	-15.644	-0.94493	4.5481	5.4674
50	979.82	990.84	1003.1	7.7751	974.4	991.99	1004	9.1329	-5.4223	1.1454	5.4339	2.9974

Device Test: 20.61 PF|DCL_48/SYNC/5/5/0/0/5/1MHz//@DUTY_SYNC_EXT_DCL50





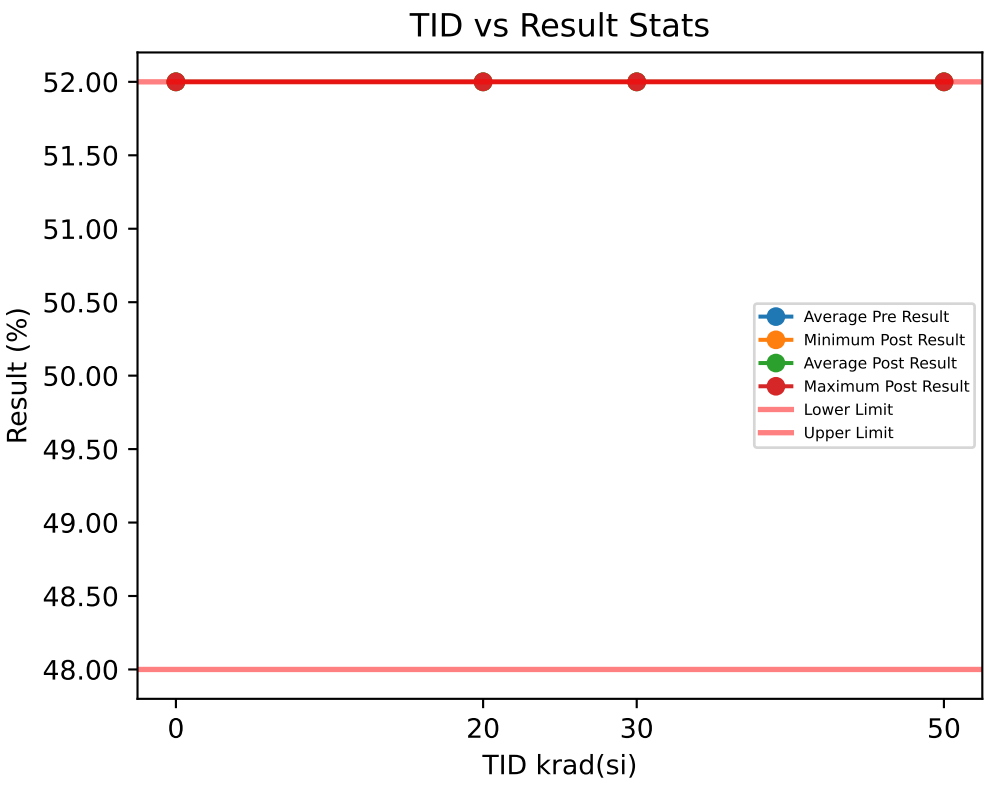
Test Results (Lower Limit = 48.0, Upper Limit = 52.0 (%))

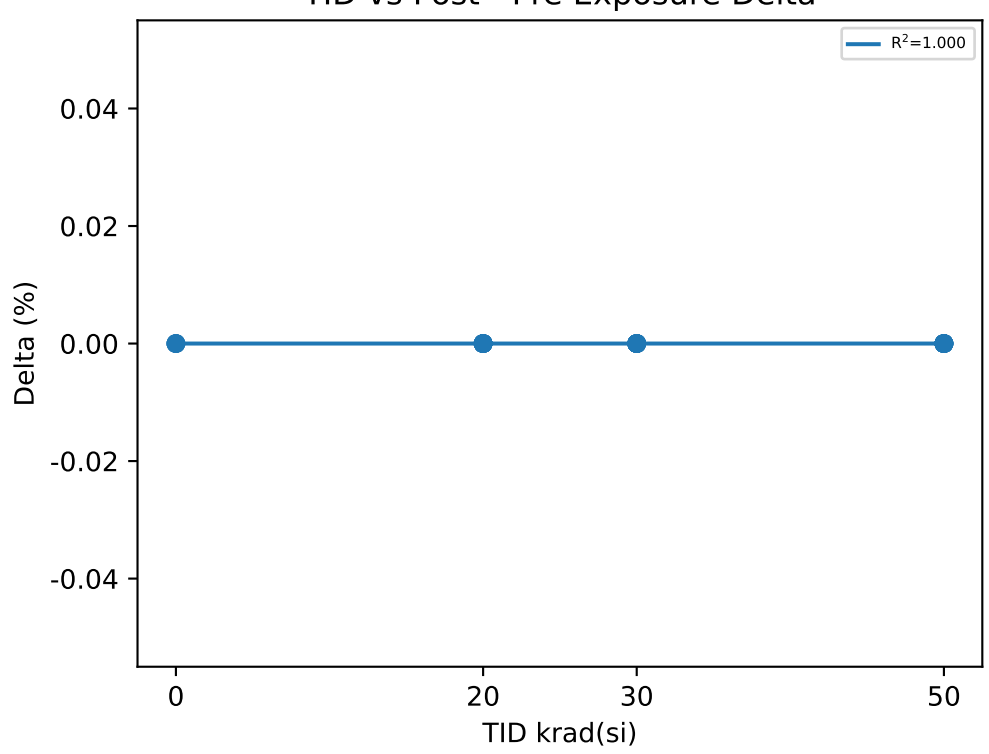
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	48	48	0
2	20	Unbiased	48	48	0
3	50	Biased	48	48	0
4	30	Unbiased	48	48	0
5	50	Unbiased	48	48	0
6	30	Biased	48	48	0
7	50	Biased	48	48	0
8	30	Unbiased	48	48	0
9	20	Unbiased	48	48	0
10	50	Biased	48	48	0
11	30	Biased	48	48	0
12	0	Correlation	48	48	0
13	0	Correlation	48	48	0
14	50	Unbiased	48	48	0
15	20	Biased	48	48	0
16	20	Unbiased	48	48	0
17	20	Biased	48	48	0
18	20	Unbiased	48	48	0
19	20	Biased	48	48	0
20	50	Unbiased	48	48	0
21	0	Correlation	48	48	0
22	50	Unbiased	48	48	0
23	0	Correlation	48	48	0
24	20	Biased	48	48	0
26	50	Biased	48	48	0
27	30	Unbiased	48	48	0
28	30	Biased	48	48	0
29	30	Unbiased	48	48	0
30	20	Biased	48	48	0
31	30	Unbiased	48	48	0
33	30	Biased	48	48	0
34	50	Unbiased	48	48	0
35	20	Unbiased	48	48	0
41	30	Biased	48	48	0

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	48	48	48	0	48	48	48	0	0	0	0	0
20	48	48	48	0	48	48	48	0	0	0	0	0
30	48	48	48	0	48	48	48	0	0	0	0	0
50	48	48	48	0	48	48	48	0	0	0	0	0

Device Test: 20.62 PF|DCL_52/SYNC/5/5/0/0/5/1MHz//@DUTY_SYNC_EXT_DCL50





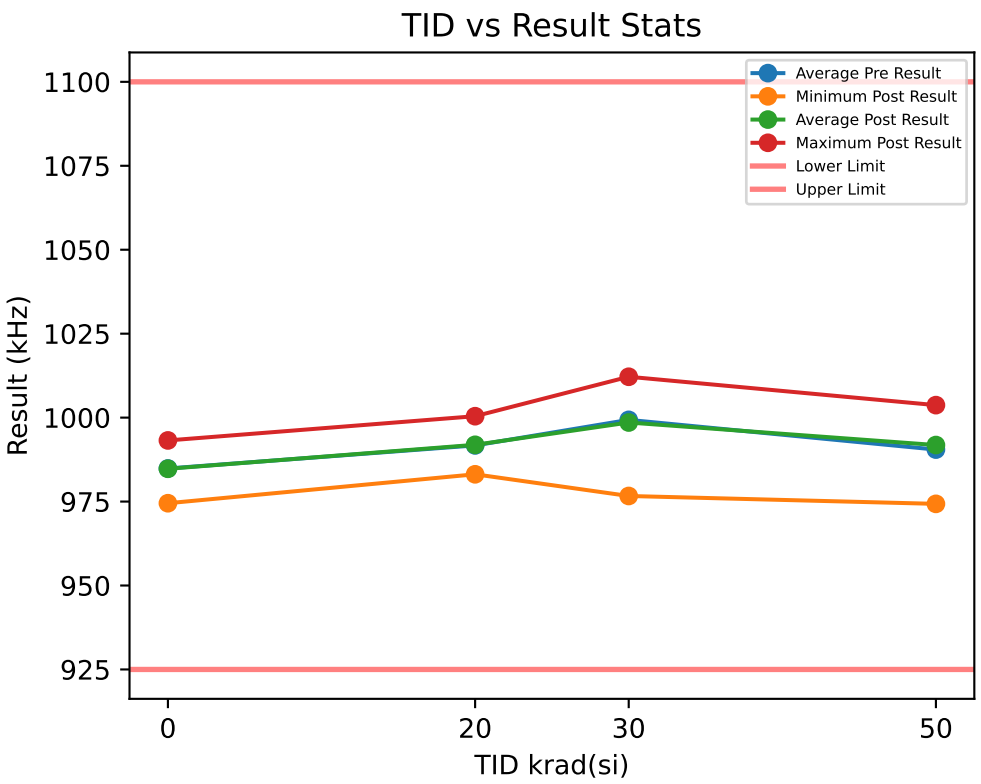
Test Results (Lower Limit = 48.0, Upper Limit = 52.0 (%))

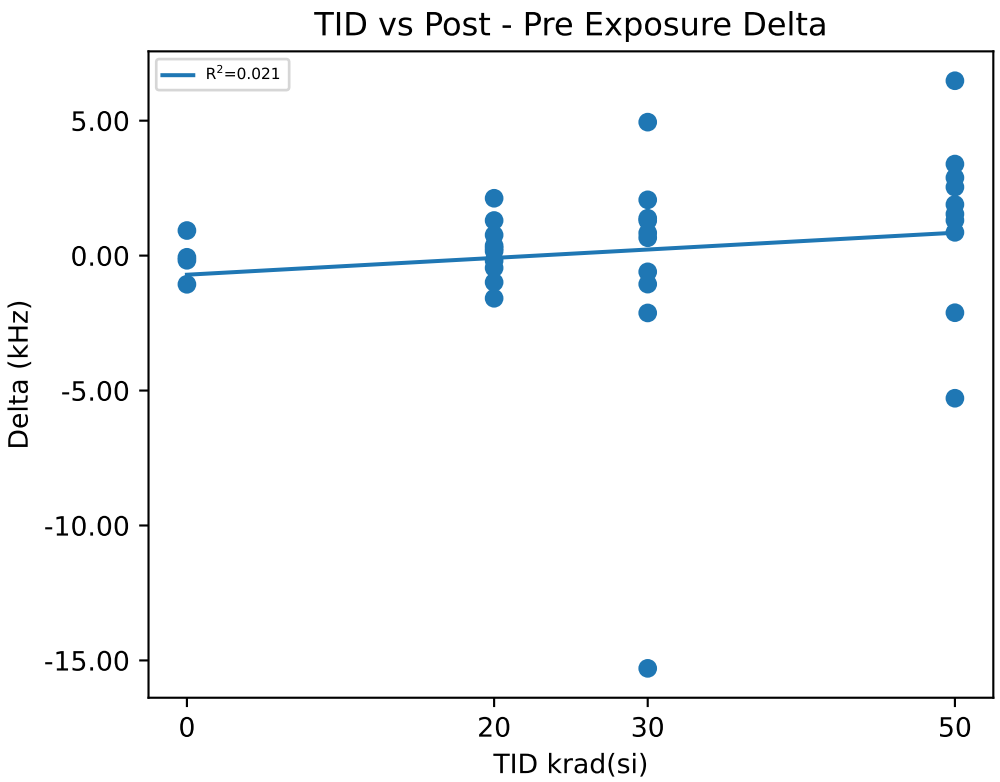
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	52	52	0
2	20	Unbiased	52	52	0
3	50	Biased	52	52	0
4	30	Unbiased	52	52	0
5	50	Unbiased	52	52	0
6	30	Biased	52	52	0
7	50	Biased	52	52	0
8	30	Unbiased	52	52	0
9	20	Unbiased	52	52	0
10	50	Biased	52	52	0
11	30	Biased	52	52	0
12	0	Correlation	52	52	0
13	0	Correlation	52	52	0
14	50	Unbiased	52	52	0
15	20	Biased	52	52	0
16	20	Unbiased	52	52	0
17	20	Biased	52	52	0
18	20	Unbiased	52	52	0
19	20	Biased	52	52	0
20	50	Unbiased	52	52	0
21	0	Correlation	52	52	0
22	50	Unbiased	52	52	0
23	0	Correlation	52	52	0
24	20	Biased	52	52	0
26	50	Biased	52	52	0
27	30	Unbiased	52	52	0
28	30	Biased	52	52	0
29	30	Unbiased	52	52	0
30	20	Biased	52	52	0
31	30	Unbiased	52	52	0
33	30	Biased	52	52	0
34	50	Unbiased	52	52	0
35	20	Unbiased	52	52	0
41	30	Biased	52	52	0

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	52	52	52	0	52	52	52	0	0	0	0	0
20	52	52	52	0	52	52	52	0	0	0	0	0
30	52	52	52	0	52	52	52	0	0	0	0	0
50	52	52	52	0	52	52	52	0	0	0	0	0

Device Test: 20.63 LEVEL|FREQ/RT/12/12/0/0/5/1MHz//@FSW_EXT_RT_D





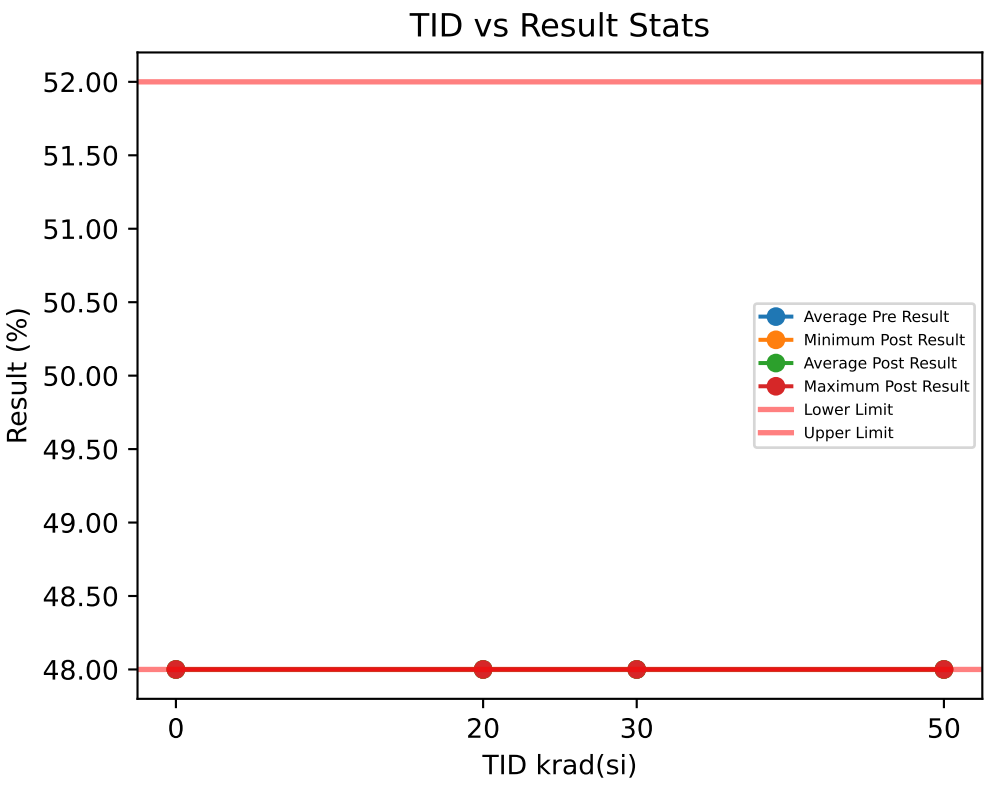
Test Results (Lower Limit = 925.0, Upper Limit = 1100.0 (kHz))

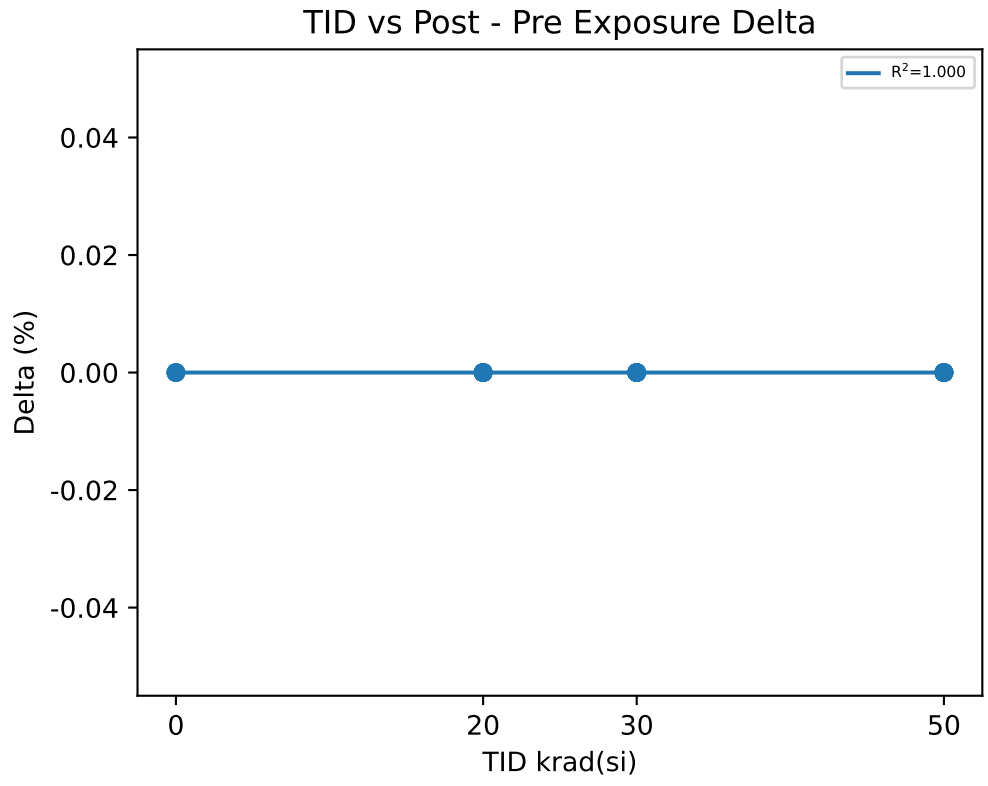
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	983.24	984.55	1.3079
2	20	Unbiased	994.9	994.71	-0.1855
3	50	Biased	1001.4	1003.3	1.8933
4	30	Unbiased	1004.8	1006.2	1.3837
5	50	Unbiased	979.6	974.32	-5.2852
6	30	Biased	991.25	996.2	4.9456
7	50	Biased	993.44	994.98	1.54
8	30	Unbiased	993.8	991.68	-2.1243
9	20	Unbiased	987.73	989.03	1.3012
10	50	Biased	996.04	999.43	3.3922
11	30	Biased	1003.8	1005.9	2.0667
12	0	Correlation	974.57	974.51	-0.0619
13	0	Correlation	979.42	980.35	0.9296
14	50	Unbiased	1002.9	1003.7	0.862
15	20	Biased	991.26	991.43	0.1688
16	20	Unbiased	984.06	984.82	0.7631
17	20	Biased	999.2	997.62	-1.5811
18	20	Unbiased	988.86	987.87	-0.988
19	20	Biased	1000.1	1000.4	0.2731
20	50	Unbiased	988.21	986.09	-2.1161
21	0	Correlation	992.05	990.99	-1.0632
22	50	Unbiased	985.81	988.35	2.5385
23	0	Correlation	993.38	993.2	-0.1738
24	20	Biased	996.43	995.98	-0.4552
26	50	Biased	989.73	992.62	2.8867
27	30	Unbiased	987.82	988.49	0.6625
28	30	Biased	1004.8	1006.1	1.2995
29	30	Unbiased	1013.2	1012.2	-1.0564
30	20	Biased	981	983.12	2.1253
31	30	Unbiased	1004.9	1004.3	-0.6011
33	30	Biased	996.97	997.81	0.8397
34	50	Unbiased	984.44	990.92	6.4798
35	20	Unbiased	993.64	994.01	0.369
41	30	Biased	991.96	976.66	-15.294

Test Statistics (kHz)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	974.57	984.85	993.38	9.305	974.51	984.76	993.2	8.844	-1.0632	-0.092325	0.9296	0.81537
20	981	991.72	1000.1	6.3338	983.12	991.9	1000.4	5.6391	-1.5811	0.17907	2.1253	1.0764
30	987.82	999.33	1013.2	8.1097	976.66	998.54	1012.2	10.649	-15.294	-0.7878	4.9456	5.4484
50	979.6	990.48	1002.9	7.8021	974.32	991.83	1003.7	9.1147	-5.2852	1.3499	6.4798	3.1775

Device Test: 20.65 PF|DCL_48/SYNC/12/12/0/0/5/1MHz//@DUTY_SYNC_EXT_DCL50





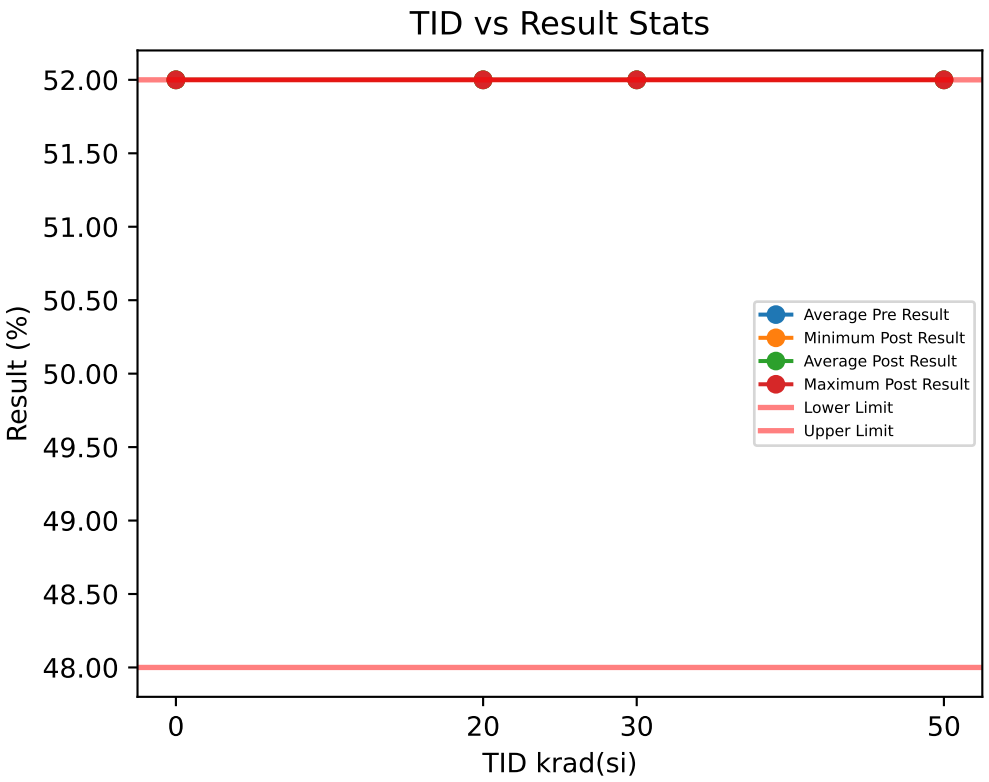
Test Results (Lower Limit = 48.0, Upper Limit = 52.0 (%))

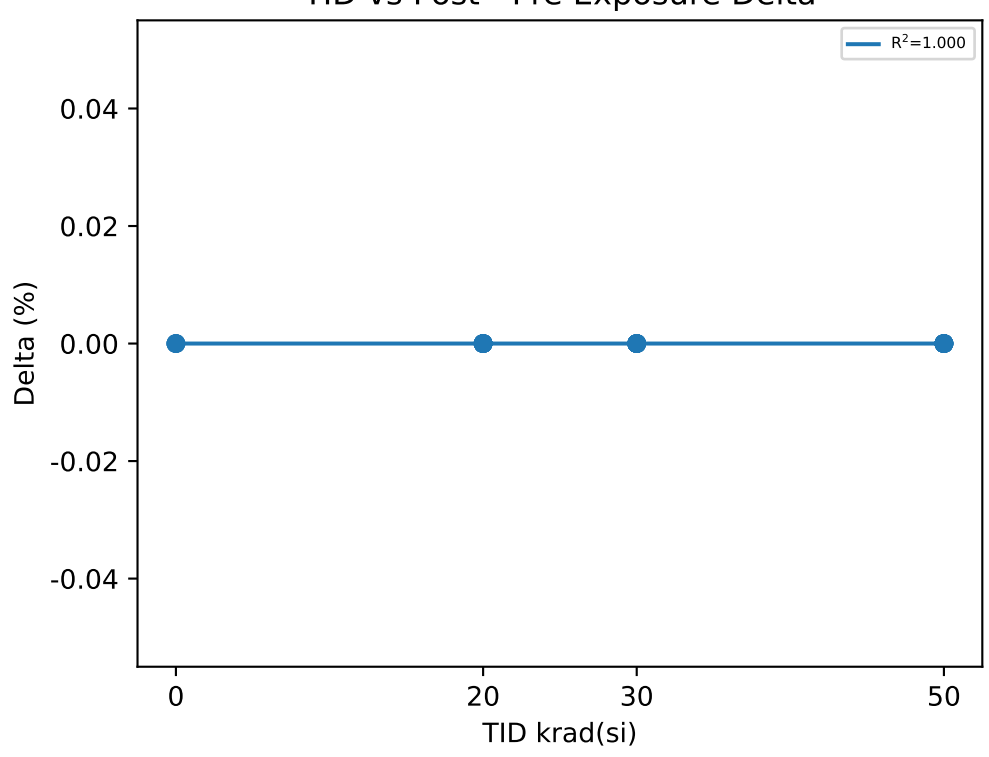
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	48	48	0
2	20	Unbiased	48	48	0
3	50	Biased	48	48	0
4	30	Unbiased	48	48	0
5	50	Unbiased	48	48	0
6	30	Biased	48	48	0
7	50	Biased	48	48	0
8	30	Unbiased	48	48	0
9	20	Unbiased	48	48	0
10	50	Biased	48	48	0
11	30	Biased	48	48	0
12	0	Correlation	48	48	0
13	0	Correlation	48	48	0
14	50	Unbiased	48	48	0
15	20	Biased	48	48	0
16	20	Unbiased	48	48	0
17	20	Biased	48	48	0
18	20	Unbiased	48	48	0
19	20	Biased	48	48	0
20	50	Unbiased	48	48	0
21	0	Correlation	48	48	0
22	50	Unbiased	48	48	0
23	0	Correlation	48	48	0
24	20	Biased	48	48	0
26	50	Biased	48	48	0
27	30	Unbiased	48	48	0
28	30	Biased	48	48	0
29	30	Unbiased	48	48	0
30	20	Biased	48	48	0
31	30	Unbiased	48	48	0
33	30	Biased	48	48	0
34	50	Unbiased	48	48	0
35	20	Unbiased	48	48	0
41	30	Biased	48	48	0

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	48	48	48	0	48	48	48	0	0	0	0	0
20	48	48	48	0	48	48	48	0	0	0	0	0
30	48	48	48	0	48	48	48	0	0	0	0	0
50	48	48	48	0	48	48	48	0	0	0	0	0

Device Test: 20.66 PF|DCL_52/SYNC/12/12/0/0/5/1MHz//@DUTY_SYNC_EXT_DCL50





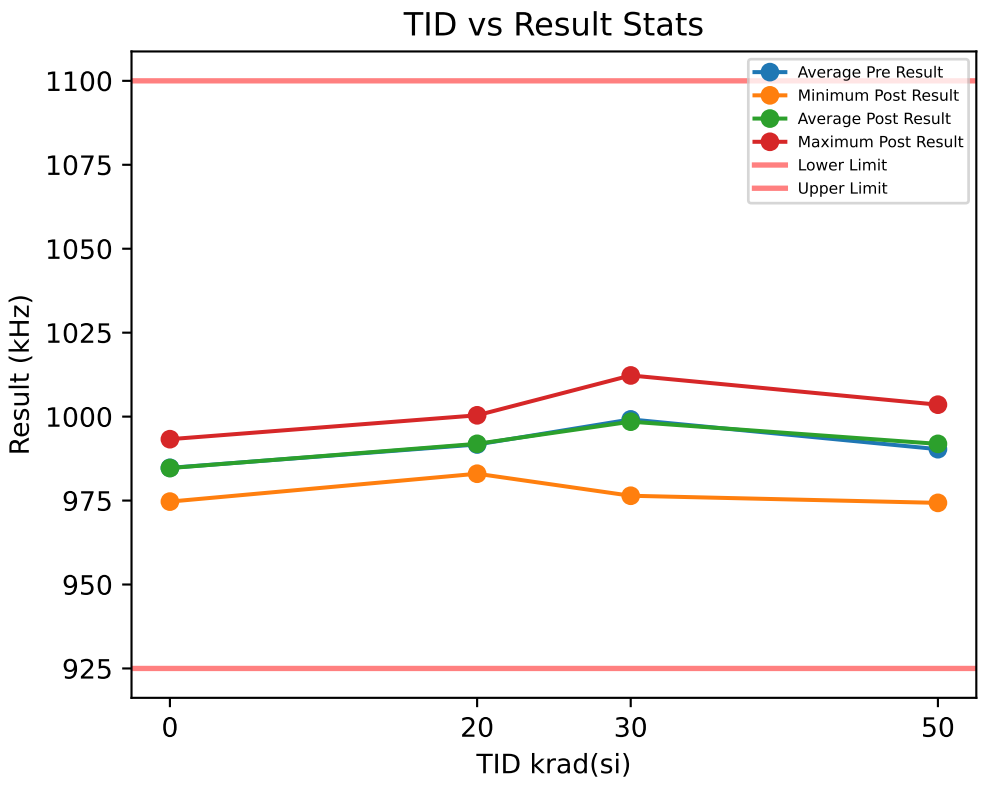
Test Results (Lower Limit = 48.0, Upper Limit = 52.0 (%))

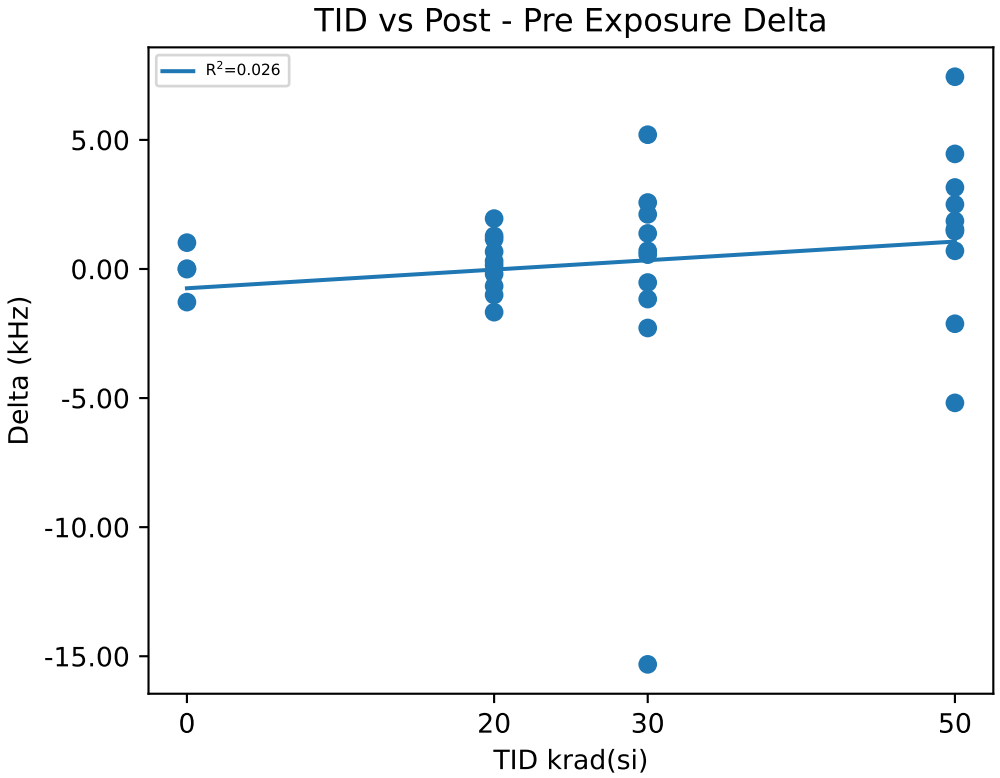
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	52	52	0
2	20	Unbiased	52	52	0
3	50	Biased	52	52	0
4	30	Unbiased	52	52	0
5	50	Unbiased	52	52	0
6	30	Biased	52	52	0
7	50	Biased	52	52	0
8	30	Unbiased	52	52	0
9	20	Unbiased	52	52	0
10	50	Biased	52	52	0
11	30	Biased	52	52	0
12	0	Correlation	52	52	0
13	0	Correlation	52	52	0
14	50	Unbiased	52	52	0
15	20	Biased	52	52	0
16	20	Unbiased	52	52	0
17	20	Biased	52	52	0
18	20	Unbiased	52	52	0
19	20	Biased	52	52	0
20	50	Unbiased	52	52	0
21	0	Correlation	52	52	0
22	50	Unbiased	52	52	0
23	0	Correlation	52	52	0
24	20	Biased	52	52	0
26	50	Biased	52	52	0
27	30	Unbiased	52	52	0
28	30	Biased	52	52	0
29	30	Unbiased	52	52	0
30	20	Biased	52	52	0
31	30	Unbiased	52	52	0
33	30	Biased	52	52	0
34	50	Unbiased	52	52	0
35	20	Unbiased	52	52	0
41	30	Biased	52	52	0

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	52	52	52	0	52	52	52	0	0	0	0	0
20	52	52	52	0	52	52	52	0	0	0	0	0
30	52	52	52	0	52	52	52	0	0	0	0	0
50	52	52	52	0	52	52	52	0	0	0	0	0

Device Test: 20.67 LEVEL|FREQ/RT/14/14/0/0/5/1MHz//@FSW_EXT_RT_D





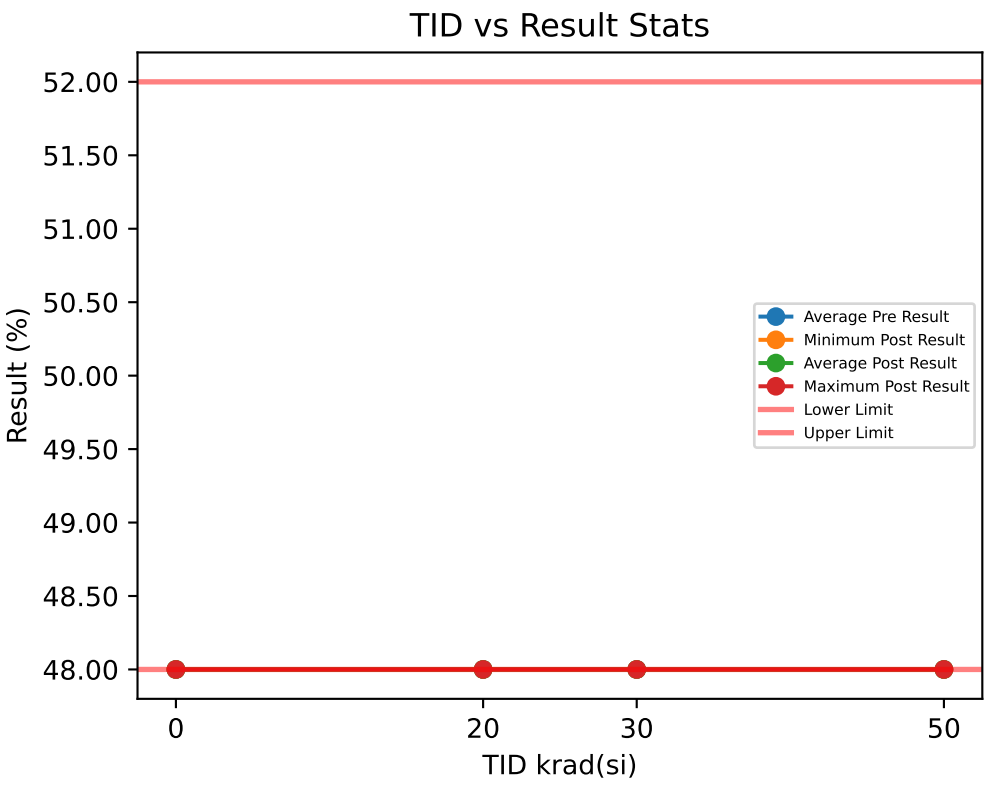
Test Results (Lower Limit = 925.0, Upper Limit = 1100.0 (kHz))

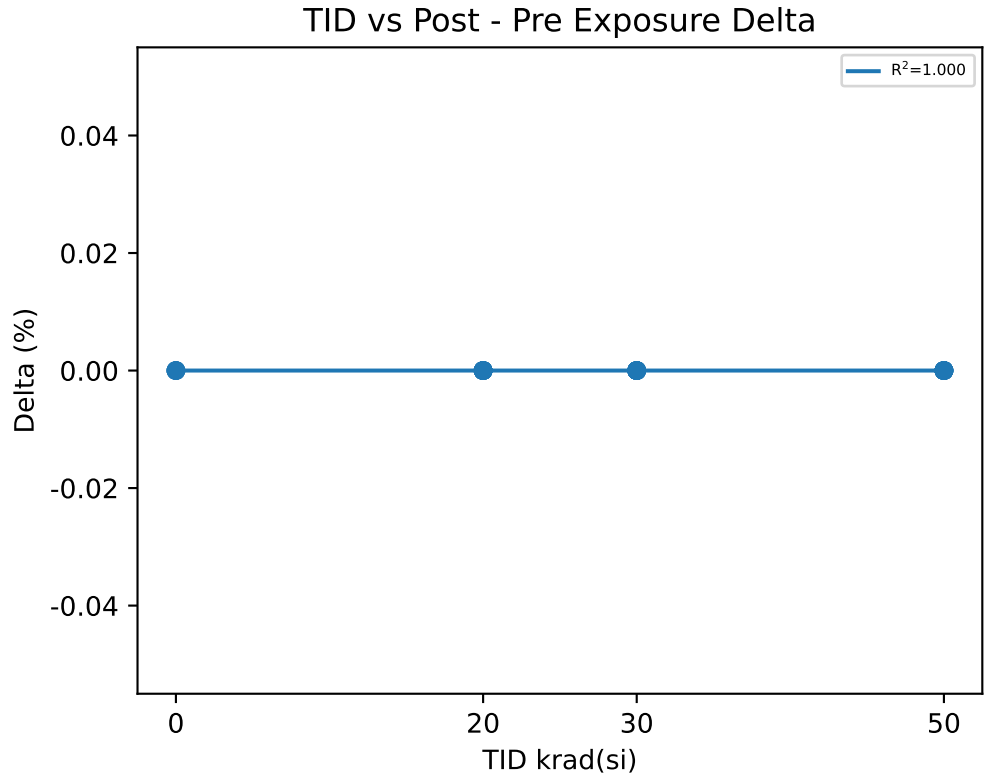
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	983.13	984.66	1.5377
2	20	Unbiased	994.9	994.7	-0.1925
3	50	Biased	1001.6	1003.5	1.8604
4	30	Unbiased	1003.8	1006.4	2.5751
5	50	Unbiased	979.5	974.31	-5.1861
6	30	Biased	991.08	996.28	5.2012
7	50	Biased	993.44	994.91	1.467
8	30	Unbiased	993.75	991.47	-2.2851
9	20	Unbiased	987.63	988.91	1.2801
10	50	Biased	995.38	999.84	4.4576
11	30	Biased	1003.7	1005.8	2.1167
12	0	Correlation	974.68	974.69	0.0113
13	0	Correlation	978.89	979.91	1.0204
14	50	Unbiased	1002.9	1003.6	0.7036
15	20	Biased	991.16	991.46	0.3065
16	20	Unbiased	983.75	984.91	1.1553
17	20	Biased	999.3	997.63	-1.6724
18	20	Unbiased	988.78	987.77	-1.0066
19	20	Biased	1000.2	1000.4	0.1465
20	50	Unbiased	988.16	986.04	-2.1211
21	0	Correlation	992.12	990.84	-1.2822
22	50	Unbiased	985.83	988.33	2.5017
23	0	Correlation	993.28	993.28	-0.0052
24	20	Biased	996.67	996.01	-0.6638
26	50	Biased	989.53	992.69	3.1572
27	30	Unbiased	987.74	988.29	0.5554
28	30	Biased	1004.7	1006.1	1.3781
29	30	Unbiased	1013.4	1012.3	-1.1648
30	20	Biased	981.04	982.99	1.9517
31	30	Unbiased	1004.7	1004.1	-0.5243
33	30	Biased	997.1	997.81	0.7066
34	50	Unbiased	983.53	990.98	7.4468
35	20	Unbiased	993.53	994.2	0.6706
41	30	Biased	991.75	976.43	-15.314

Test Statistics (kHz)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	974.68	984.74	993.28	9.3626	974.69	984.68	993.28	8.8403	-1.2822	-0.063925	1.0204	0.94323
20	981.04	991.7	1000.2	6.4229	982.99	991.9	1000.4	5.6704	-1.6724	0.19754	1.9517	1.1178
30	987.74	999.17	1013.4	8.1013	976.43	998.49	1012.3	10.749	-15.314	-0.67556	5.2012	5.5547
50	979.5	990.3	1002.9	7.8942	974.31	991.88	1003.6	9.145	-5.1861	1.5825	7.4468	3.438

Device Test: 20.69 PF|DCL_48/SYNC/14/14/0/0/5/1MHz//@DUTY_SYNC_EXT_DCL50





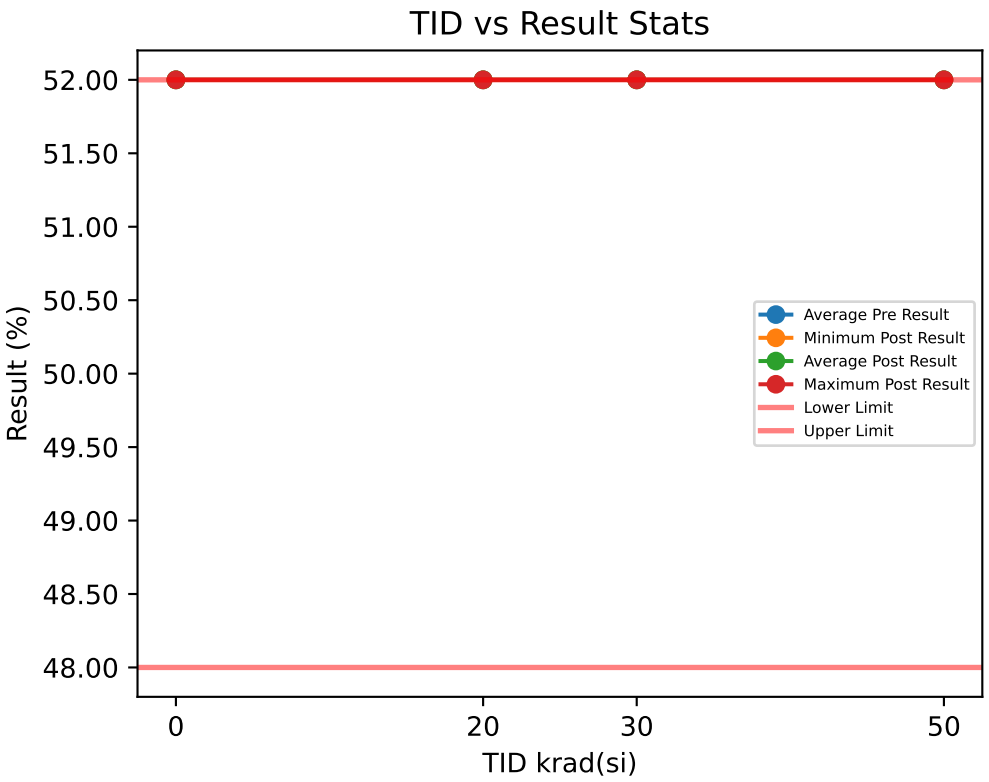
Test Results (Lower Limit = 48.0, Upper Limit = 52.0 (%))

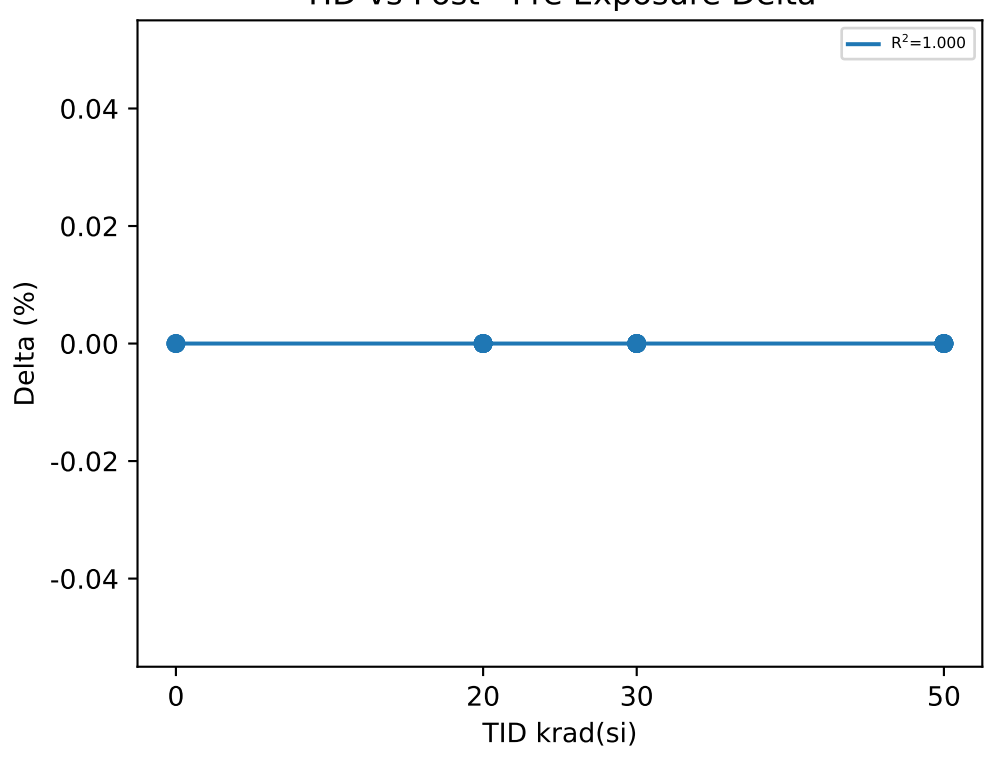
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	48	48	0
2	20	Unbiased	48	48	0
3	50	Biased	48	48	0
4	30	Unbiased	48	48	0
5	50	Unbiased	48	48	0
6	30	Biased	48	48	0
7	50	Biased	48	48	0
8	30	Unbiased	48	48	0
9	20	Unbiased	48	48	0
10	50	Biased	48	48	0
11	30	Biased	48	48	0
12	0	Correlation	48	48	0
13	0	Correlation	48	48	0
14	50	Unbiased	48	48	0
15	20	Biased	48	48	0
16	20	Unbiased	48	48	0
17	20	Biased	48	48	0
18	20	Unbiased	48	48	0
19	20	Biased	48	48	0
20	50	Unbiased	48	48	0
21	0	Correlation	48	48	0
22	50	Unbiased	48	48	0
23	0	Correlation	48	48	0
24	20	Biased	48	48	0
26	50	Biased	48	48	0
27	30	Unbiased	48	48	0
28	30	Biased	48	48	0
29	30	Unbiased	48	48	0
30	20	Biased	48	48	0
31	30	Unbiased	48	48	0
33	30	Biased	48	48	0
34	50	Unbiased	48	48	0
35	20	Unbiased	48	48	0
41	30	Biased	48	48	0

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	48	48	48	0	48	48	48	0	0	0	0	0
20	48	48	48	0	48	48	48	0	0	0	0	0
30	48	48	48	0	48	48	48	0	0	0	0	0
50	48	48	48	0	48	48	48	0	0	0	0	0

Device Test: 20.70 PF|DCL_52/SYNC/14/14/0/0/5/1MHz//@DUTY_SYNC_EXT_DCL50





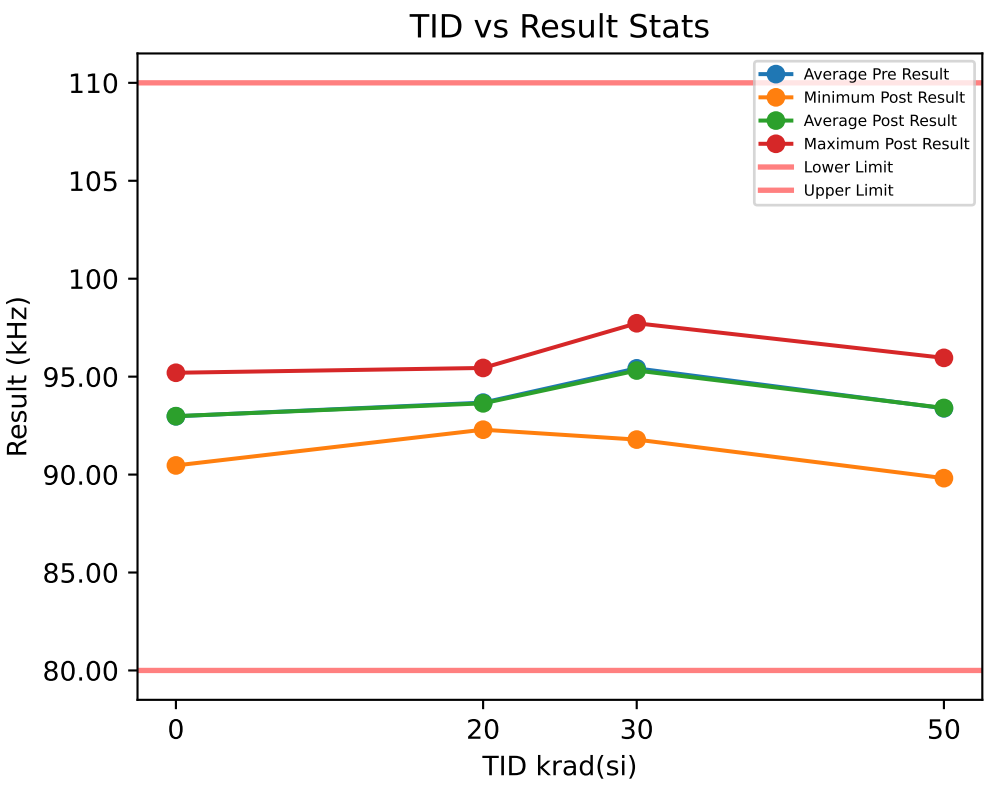
Test Results (Lower Limit = 48.0, Upper Limit = 52.0 (%))

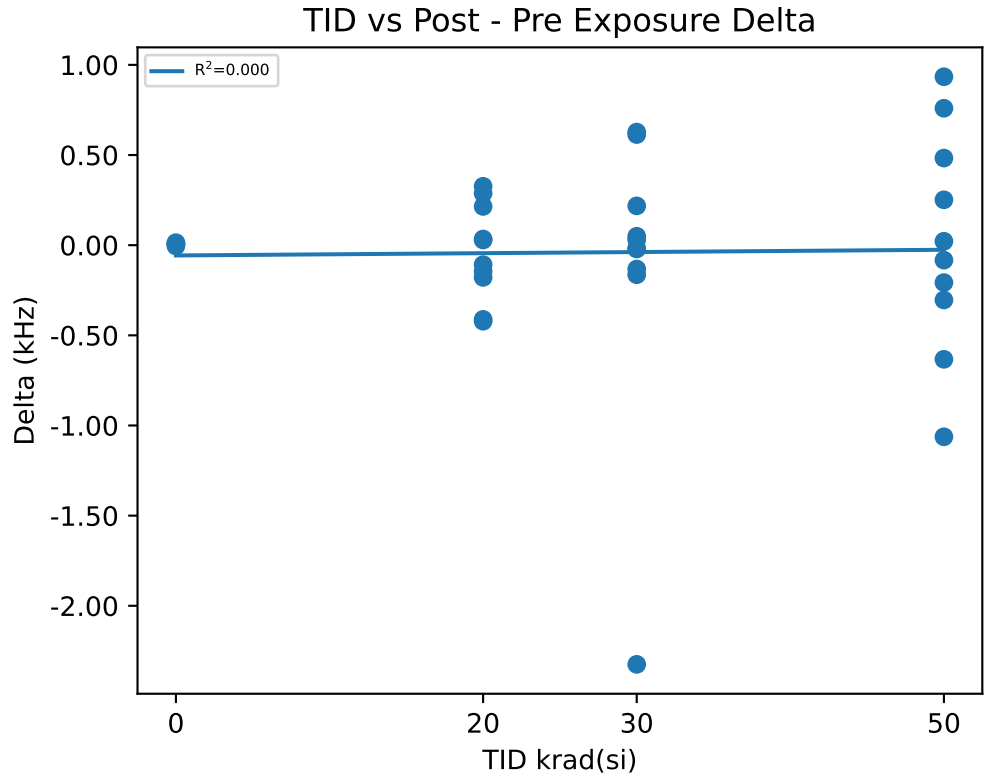
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	52	52	0
2	20	Unbiased	52	52	0
3	50	Biased	52	52	0
4	30	Unbiased	52	52	0
5	50	Unbiased	52	52	0
6	30	Biased	52	52	0
7	50	Biased	52	52	0
8	30	Unbiased	52	52	0
9	20	Unbiased	52	52	0
10	50	Biased	52	52	0
11	30	Biased	52	52	0
12	0	Correlation	52	52	0
13	0	Correlation	52	52	0
14	50	Unbiased	52	52	0
15	20	Biased	52	52	0
16	20	Unbiased	52	52	0
17	20	Biased	52	52	0
18	20	Unbiased	52	52	0
19	20	Biased	52	52	0
20	50	Unbiased	52	52	0
21	0	Correlation	52	52	0
22	50	Unbiased	52	52	0
23	0	Correlation	52	52	0
24	20	Biased	52	52	0
26	50	Biased	52	52	0
27	30	Unbiased	52	52	0
28	30	Biased	52	52	0
29	30	Unbiased	52	52	0
30	20	Biased	52	52	0
31	30	Unbiased	52	52	0
33	30	Biased	52	52	0
34	50	Unbiased	52	52	0
35	20	Unbiased	52	52	0
41	30	Biased	52	52	0

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	52	52	52	0	52	52	52	0	0	0	0	0
20	52	52	52	0	52	52	52	0	0	0	0	0
30	52	52	52	0	52	52	52	0	0	0	0	0
50	52	52	52	0	52	52	52	0	0	0	0	0

Device Test: 20.71 LEVEL|FREQ/RT/4.5/4.5/0/1000/4.5/100kHz//@FSW_EXT_RT_A





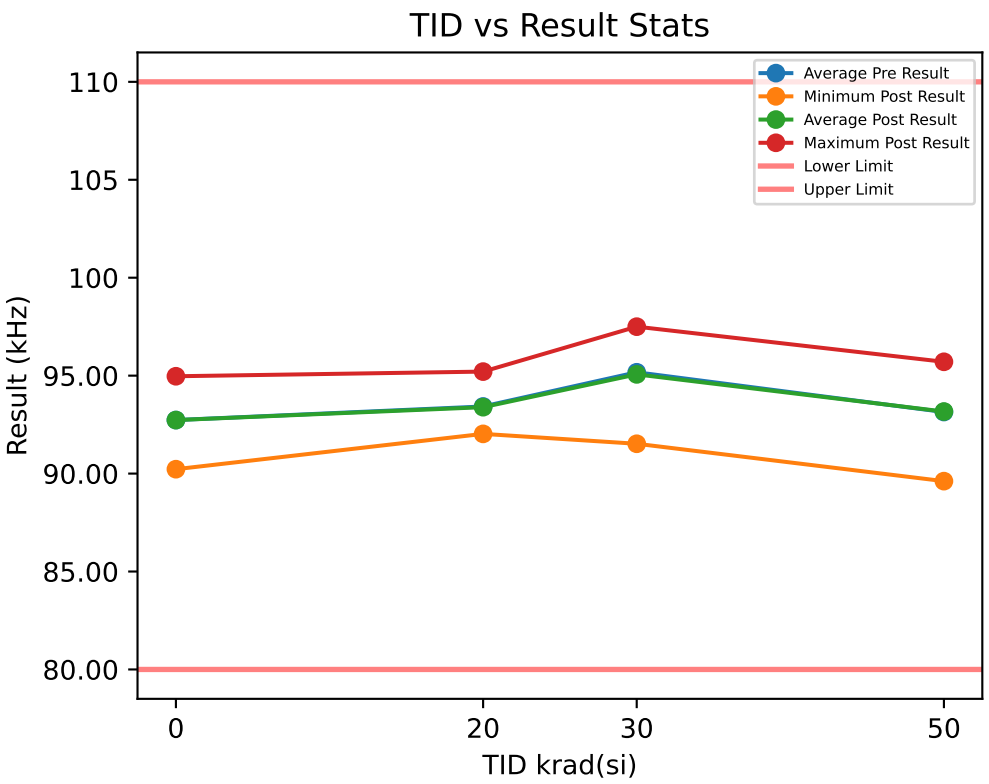
Test Results (Lower Limit = 80.0, Upper Limit = 110.0 (kHz))

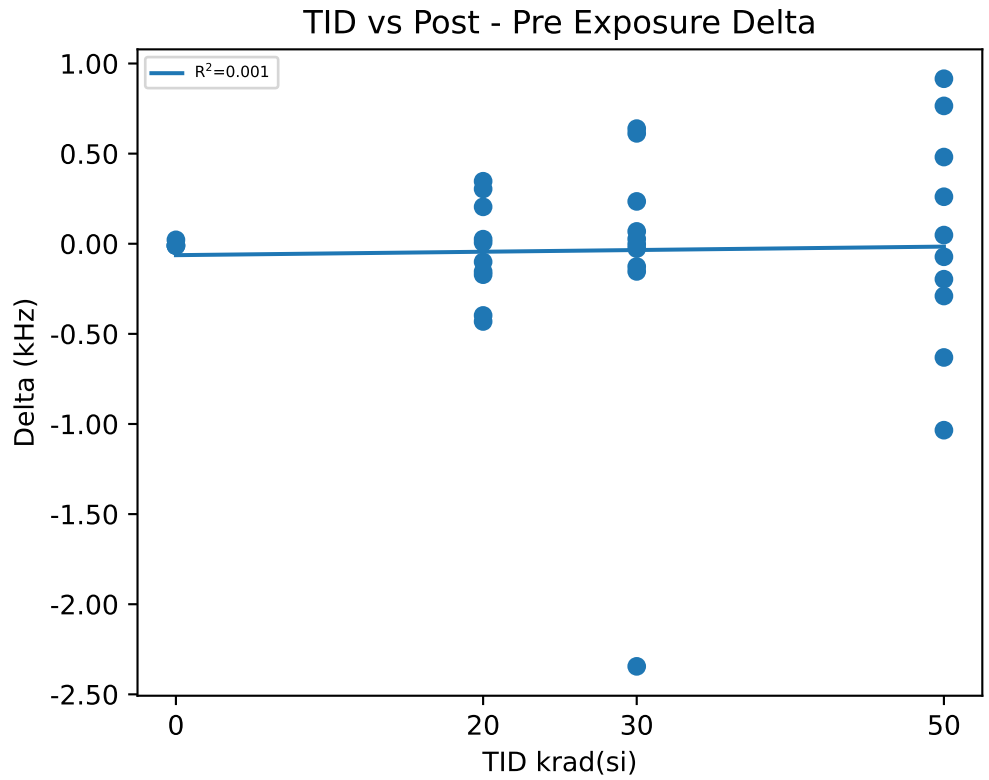
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	91.897	91.593	-0.3038
2	20	Unbiased	93.943	93.798	-0.145
3	50	Biased	94.448	94.931	0.4831
4	30	Unbiased	95.774	95.642	-0.1324
5	50	Unbiased	90.88	89.817	-1.0626
6	30	Biased	93.623	94.236	0.6136
7	50	Biased	94.201	93.993	-0.2074
8	30	Unbiased	94.932	94.982	0.0494
9	20	Unbiased	92.4	92.292	-0.108
10	50	Biased	95.23	95.481	0.2517
11	30	Biased	95.909	96.536	0.6273
12	0	Correlation	90.453	90.467	0.0138
13	0	Correlation	93.126	93.133	0.0069
14	50	Unbiased	96.042	95.959	-0.083
15	20	Biased	93.428	93.716	0.2875
16	20	Unbiased	92.777	93.103	0.3266
17	20	Biased	95.855	95.444	-0.4115
18	20	Unbiased	94.067	93.645	-0.4217
19	20	Biased	93.539	93.36	-0.1787
20	50	Unbiased	93.258	92.625	-0.6329
21	0	Correlation	93.122	93.131	0.0094
22	50	Unbiased	92.808	92.829	0.0217
23	0	Correlation	95.203	95.198	-0.0045
24	20	Biased	93.839	93.874	0.0343
26	50	Biased	93.67	94.43	0.7594
27	30	Unbiased	92.974	92.953	-0.021
28	30	Biased	97.694	97.725	0.0308
29	30	Unbiased	97.779	97.615	-0.1639
30	20	Biased	93.118	93.333	0.2149
31	30	Unbiased	96.892	96.875	-0.0172
33	30	Biased	94.554	94.772	0.2179
34	50	Unbiased	91.408	92.342	0.9342
35	20	Unbiased	93.777	93.806	0.0286
41	30	Biased	94.111	91.787	-2.3248

Test Statistics (kHz)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	90.453	92.976	95.203	1.9465	90.467	92.982	95.198	1.9393	-0.0045	0.0064	0.0138	0.0078064
20	92.4	93.674	95.855	0.93328	92.292	93.637	95.444	0.79197	-0.4217	-0.0373	0.3266	0.2657
30	92.974	95.424	97.779	1.6728	91.787	95.312	97.725	1.9644	-2.3248	-0.11203	0.6273	0.82632
50	90.88	93.384	96.042	1.6696	89.817	93.4	95.959	1.9086	-1.0626	0.01604	0.9342	0.61607

Device Test: 20.73 LEVEL|FREQ/RT/5/5/0/1000/5/100kHz//@FSW_EXT_RT_A





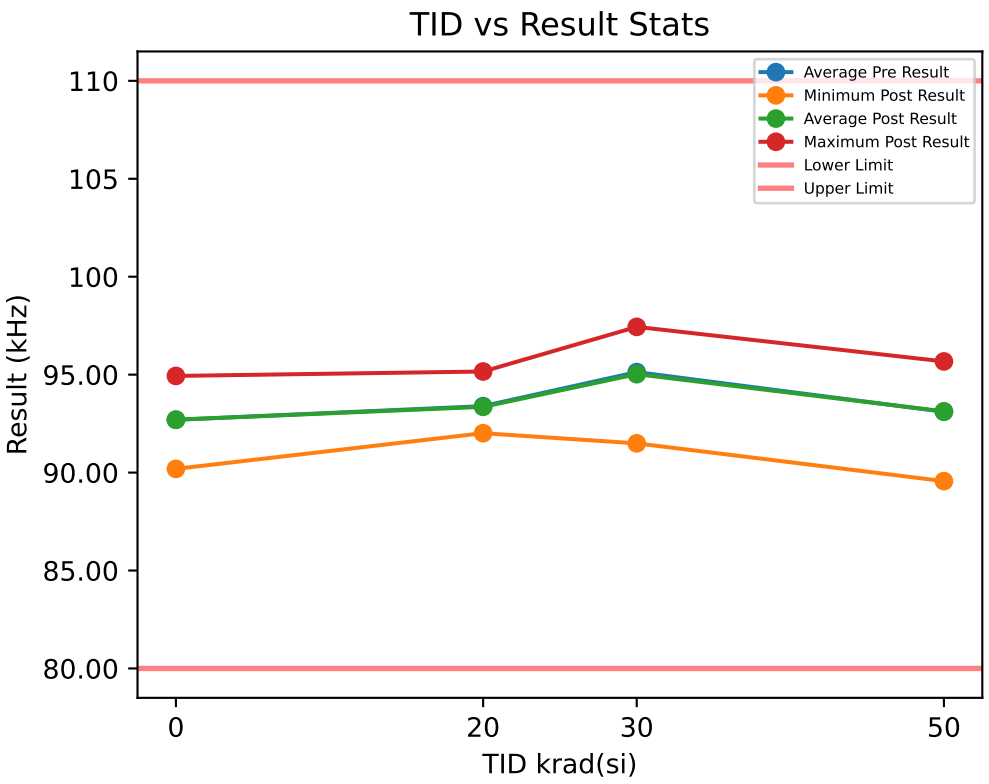
Test Results (Lower Limit = 80.0, Upper Limit = 110.0 (kHz))

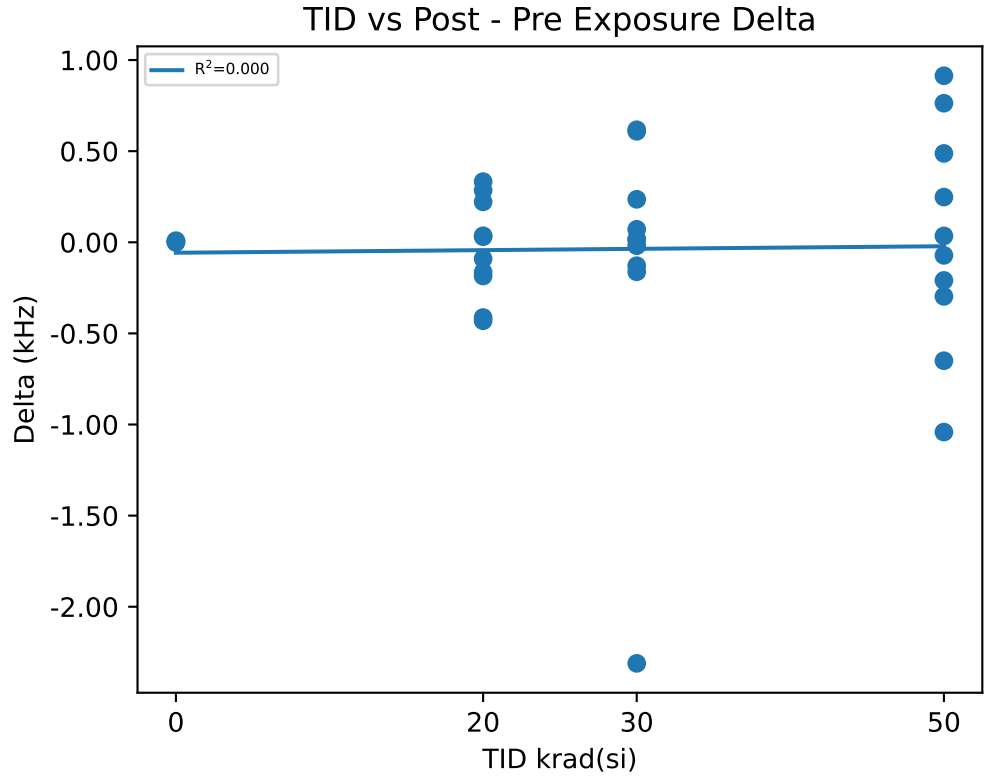
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	91.657	91.367	-0.29
2	20	Unbiased	93.712	93.558	-0.1542
3	50	Biased	94.198	94.679	0.481
4	30	Unbiased	95.517	95.39	-0.1266
5	50	Unbiased	90.648	89.614	-1.0344
6	30	Biased	93.368	93.981	0.6124
7	50	Biased	93.944	93.748	-0.1967
8	30	Unbiased	94.664	94.733	0.0685
9	20	Unbiased	92.127	92.027	-0.1005
10	50	Biased	94.986	95.247	0.2608
11	30	Biased	95.645	96.284	0.6388
12	0	Correlation	90.202	90.224	0.0217
13	0	Correlation	92.87	92.859	-0.0105
14	50	Unbiased	95.779	95.707	-0.0723
15	20	Biased	93.145	93.449	0.304
16	20	Unbiased	92.544	92.891	0.3468
17	20	Biased	95.604	95.207	-0.3977
18	20	Unbiased	93.82	93.389	-0.4313
19	20	Biased	93.303	93.132	-0.1716
20	50	Unbiased	93.039	92.408	-0.6309
21	0	Correlation	92.883	92.873	-0.0103
22	50	Unbiased	92.566	92.614	0.0481
23	0	Correlation	94.979	94.969	-0.0102
24	20	Biased	93.597	93.623	0.0254
26	50	Biased	93.434	94.199	0.7648
27	30	Unbiased	92.708	92.682	-0.0268
28	30	Biased	97.474	97.5	0.0267
29	30	Unbiased	97.537	97.383	-0.1535
30	20	Biased	92.856	93.061	0.2047
31	30	Unbiased	96.615	96.612	-0.0028
33	30	Biased	94.323	94.558	0.2349
34	50	Unbiased	91.183	92.098	0.9155
35	20	Unbiased	93.555	93.561	0.0068
41	30	Biased	93.867	91.522	-2.3447

Test Statistics (kHz)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	90.202	92.734	94.979	1.9571	90.224	92.731	94.969	1.9433	-0.0105	-0.002325	0.0217	0.016017
20	92.127	93.426	95.604	0.9376	92.027	93.39	95.207	0.79566	-0.4313	-0.03676	0.3468	0.26859
30	92.708	95.172	97.537	1.6772	91.522	95.065	97.5	1.9739	-2.3447	-0.10731	0.6388	0.83443
50	90.648	93.143	95.779	1.6602	89.614	93.168	95.707	1.8961	-1.0344	0.02459	0.9155	0.60688

Device Test: 20.75 LEVEL|FREQ/RT/12/12/0/1000/5/100kHz//@FSW_EXT_RT_A





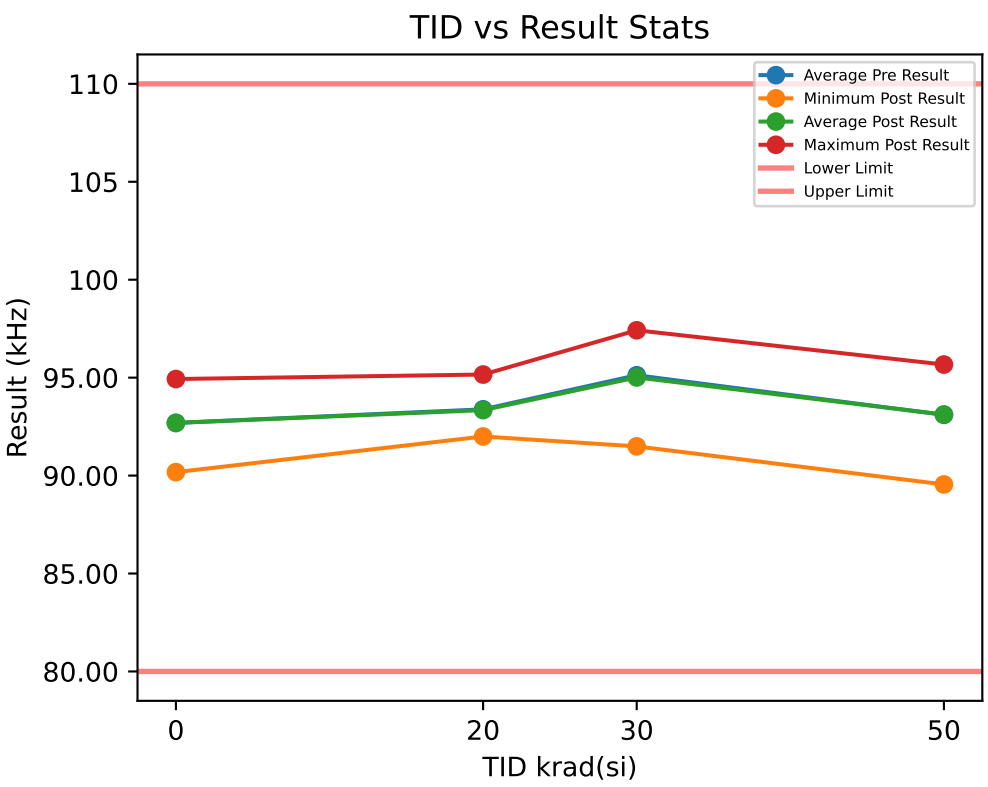
Test Results (Lower Limit = 80.0, Upper Limit = 110.0 (kHz))

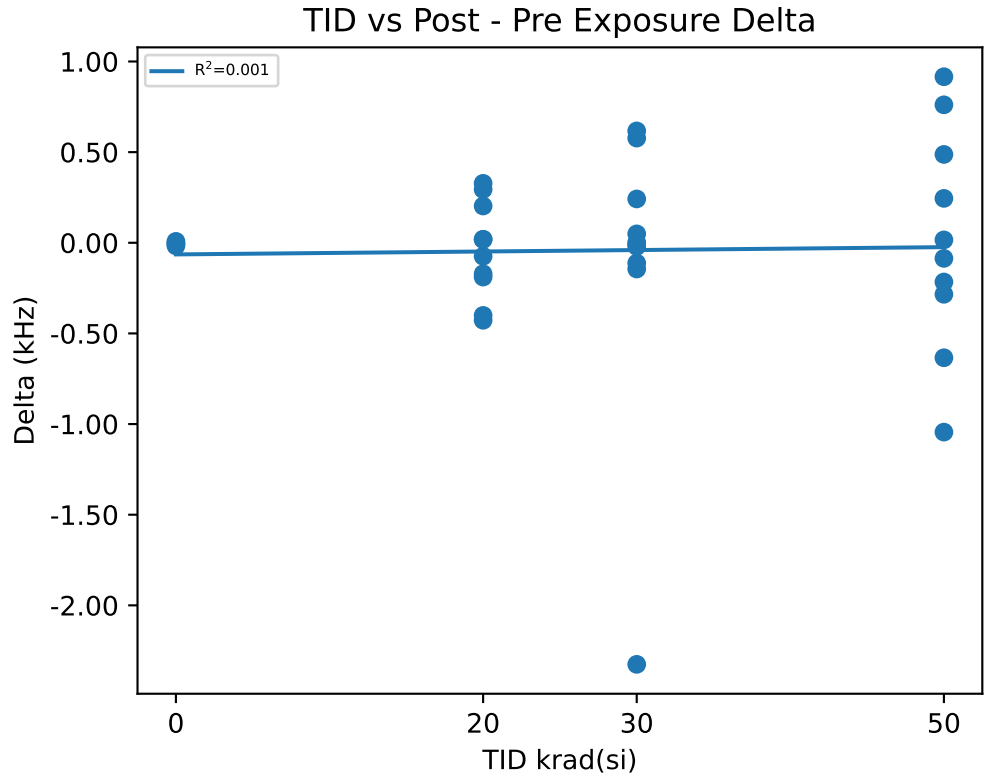
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	91.62	91.323	-0.2969
2	20	Unbiased	93.679	93.514	-0.1641
3	50	Biased	94.144	94.632	0.4876
4	30	Unbiased	95.478	95.349	-0.1286
5	50	Unbiased	90.606	89.564	-1.0415
6	30	Biased	93.331	93.94	0.6088
7	50	Biased	93.905	93.696	-0.2094
8	30	Unbiased	94.636	94.708	0.0712
9	20	Unbiased	92.103	92.012	-0.0907
10	50	Biased	94.959	95.207	0.2481
11	30	Biased	95.622	96.239	0.6174
12	0	Correlation	90.191	90.189	-0.0013
13	0	Correlation	92.823	92.827	0.0042
14	50	Unbiased	95.747	95.675	-0.0718
15	20	Biased	93.116	93.401	0.2851
16	20	Unbiased	92.521	92.853	0.3328
17	20	Biased	95.573	95.16	-0.4129
18	20	Unbiased	93.786	93.356	-0.4308
19	20	Biased	93.275	93.09	-0.1852
20	50	Unbiased	93.01	92.36	-0.65
21	0	Correlation	92.839	92.848	0.0088
22	50	Unbiased	92.541	92.576	0.0349
23	0	Correlation	94.931	94.935	0.0043
24	20	Biased	93.558	93.594	0.0358
26	50	Biased	93.4	94.163	0.7631
27	30	Unbiased	92.665	92.646	-0.0188
28	30	Biased	97.421	97.439	0.0172
29	30	Unbiased	97.498	97.335	-0.1621
30	20	Biased	92.816	93.038	0.2217
31	30	Unbiased	96.567	96.581	0.0144
33	30	Biased	94.274	94.51	0.2358
34	50	Unbiased	91.137	92.051	0.9139
35	20	Unbiased	93.501	93.532	0.0305
41	30	Biased	93.803	91.492	-2.3107

Test Statistics (kHz)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	90.191	92.696	94.931	1.9413	90.189	92.7	94.935	1.9438	-0.0013	0.004	0.0088	0.0041336
20	92.103	93.393	95.573	0.93546	92.012	93.355	95.16	0.78877	-0.4308	-0.03778	0.3328	0.2697
30	92.665	95.13	97.498	1.6777	91.492	95.024	97.439	1.9678	-2.3107	-0.10554	0.6174	0.8222
50	90.606	93.107	95.747	1.6625	89.564	93.125	95.675	1.8996	-1.0415	0.0178	0.9139	0.61094

Device Test: 20.77 LEVEL|FREQ/RT/14/14/0/1000/5/100kHz//@FSW_EXT_RT_A





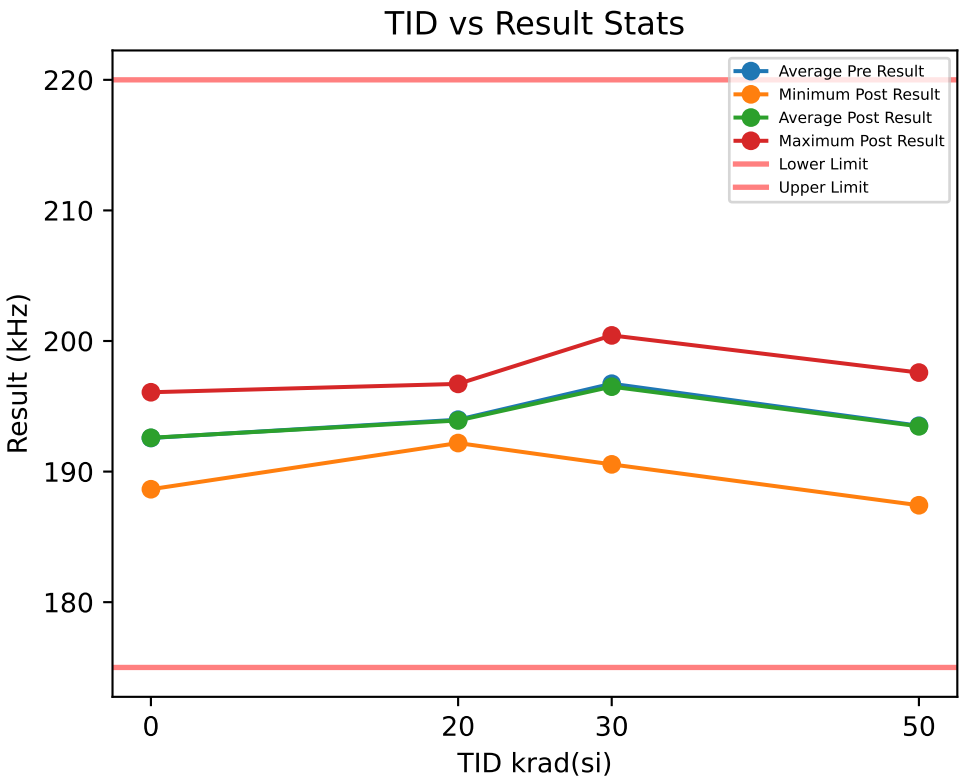
Test Results (Lower Limit = 80.0, Upper Limit = 110.0 (kHz))

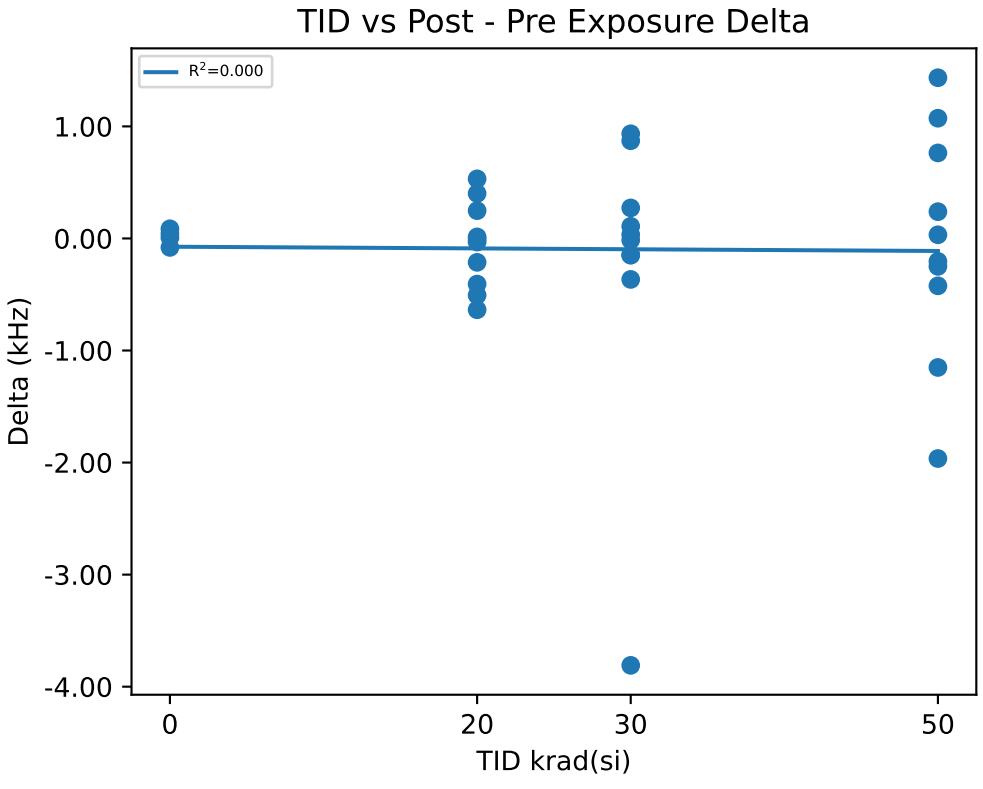
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	91.604	91.32	-0.2841
2	20	Unbiased	93.67	93.499	-0.171
3	50	Biased	94.139	94.626	0.4873
4	30	Unbiased	95.469	95.357	-0.1122
5	50	Unbiased	90.592	89.548	-1.0444
6	30	Biased	93.337	93.915	0.5774
7	50	Biased	93.897	93.68	-0.2163
8	30	Unbiased	94.63	94.679	0.0491
9	20	Unbiased	92.07	91.996	-0.0744
10	50	Biased	94.946	95.191	0.2449
11	30	Biased	95.603	96.22	0.617
12	0	Correlation	90.181	90.175	-0.0058
13	0	Correlation	92.821	92.804	-0.017
14	50	Unbiased	95.755	95.669	-0.086
15	20	Biased	93.106	93.4	0.2942
16	20	Unbiased	92.511	92.838	0.3279
17	20	Biased	95.559	95.159	-0.4006
18	20	Unbiased	93.779	93.352	-0.4275
19	20	Biased	93.268	93.079	-0.1891
20	50	Unbiased	92.997	92.363	-0.6342
21	0	Correlation	92.831	92.839	0.0078
22	50	Unbiased	92.541	92.557	0.0159
23	0	Correlation	94.931	94.93	-0.0016
24	20	Biased	93.558	93.576	0.0183
26	50	Biased	93.4	94.161	0.761
27	30	Unbiased	92.664	92.644	-0.0202
28	30	Biased	97.416	97.418	0.002
29	30	Unbiased	97.471	97.326	-0.1446
30	20	Biased	92.813	93.016	0.2029
31	30	Unbiased	96.561	96.551	-0.0093
33	30	Biased	94.262	94.504	0.2418
34	50	Unbiased	91.138	92.054	0.9159
35	20	Unbiased	93.492	93.511	0.0195
41	30	Biased	93.817	91.491	-2.3255

Test Statistics (kHz)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	90.181	92.691	94.931	1.9456	90.175	92.687	94.93	1.9473	-0.017	-0.00415	0.0078	0.010282
20	92.07	93.383	95.559	0.93796	91.996	93.343	95.159	0.79258	-0.4275	-0.03998	0.3279	0.26536
30	92.664	95.123	97.471	1.6704	91.491	95.011	97.418	1.9627	-2.3255	-0.11245	0.617	0.82263
50	90.592	93.101	95.755	1.6654	89.548	93.117	95.669	1.8997	-1.0444	0.016	0.9159	0.60928

Device Test: 20.79 LEVEL|FREQ/RT/4.5/4.5/0/1000/4.5/200kHz//@FSW_EXT_RT_B





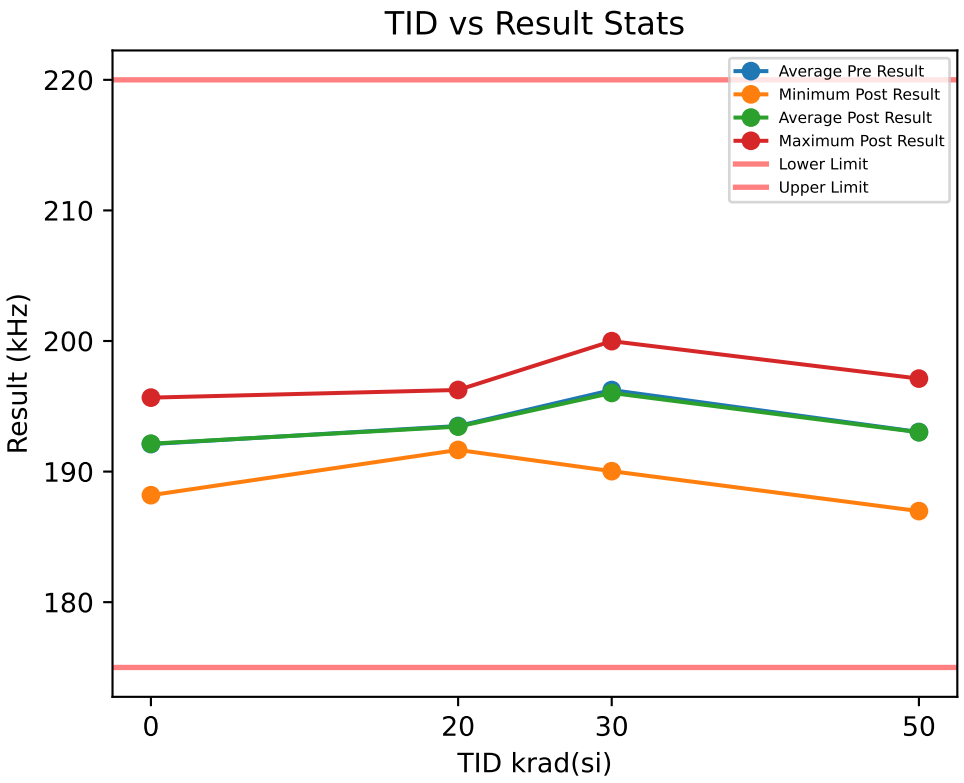
Test Results (Lower Limit = 175.0, Upper Limit = 220.0 (kHz))

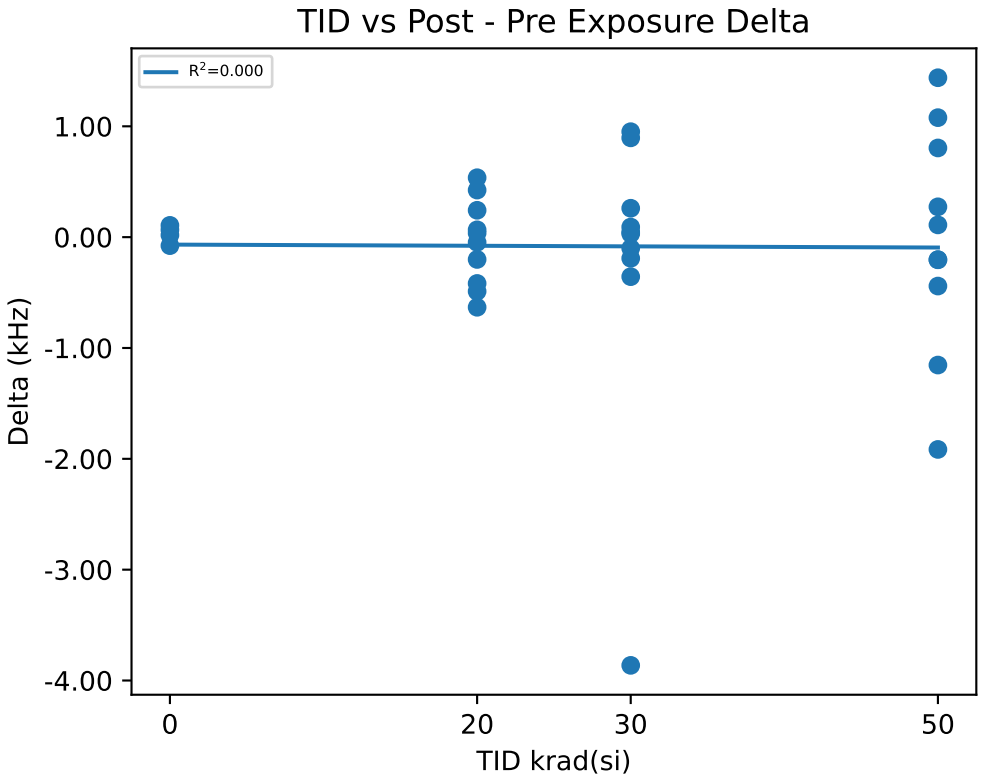
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	191.02	190.6	-0.4227
2	20	Unbiased	194.61	194.2	-0.4071
3	50	Biased	195.6	196.37	0.7633
4	30	Unbiased	197.7	197.55	-0.1472
5	50	Unbiased	189.38	187.42	-1.9639
6	30	Biased	193.86	194.8	0.9341
7	50	Biased	194.74	194.49	-0.2491
8	30	Unbiased	195.67	195.66	-0.0148
9	20	Unbiased	192.22	192.19	-0.0323
10	50	Biased	196.41	196.65	0.2389
11	30	Biased	197.63	198.5	0.8721
12	0	Correlation	188.73	188.65	-0.08
13	0	Correlation	192.36	192.37	0.0067
14	50	Unbiased	197.79	197.58	-0.2046
15	20	Biased	193.4	193.8	0.4014
16	20	Unbiased	192.23	192.76	0.5318
17	20	Biased	197.22	196.72	-0.5064
18	20	Unbiased	194.18	193.54	-0.6363
19	20	Biased	194.48	194.27	-0.2132
20	50	Unbiased	193.26	192.11	-1.1513
21	0	Correlation	193.21	193.26	0.0433
22	50	Unbiased	192.54	192.57	0.0327
23	0	Correlation	195.99	196.07	0.0862
24	20	Biased	194.63	194.64	0.0138
26	50	Biased	193.79	194.86	1.0729
27	30	Unbiased	192.67	192.71	0.0353
28	30	Biased	200.16	200.01	-0.1492
29	30	Unbiased	200.8	200.43	-0.3656
30	20	Biased	192.48	192.72	0.248
31	30	Unbiased	198.89	199	0.1086
33	30	Biased	195.55	195.82	0.2725
34	50	Unbiased	190.57	192	1.4342
35	20	Unbiased	194.3	194.29	-0.0068
41	30	Biased	194.36	190.55	-3.8097

Test Statistics (kHz)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	188.73	192.57	195.99	2.995	188.65	192.59	196.07	3.065	-0.08	0.01405	0.0862	0.070618
20	192.22	193.97	197.22	1.5086	192.19	193.91	196.72	1.274	-0.6363	-0.06071	0.5318	0.3862
30	192.67	196.73	200.8	2.7387	190.55	196.5	200.43	3.2135	-3.8097	-0.22639	0.9341	1.3291
50	189.38	193.51	197.79	2.6986	187.42	193.46	197.58	3.1277	-1.9639	-0.04496	1.4342	1.0162

Device Test: 20.81 LEVEL|FREQ/RT/5/5/0/1000/5/200kHz//@FSW_EXT_RT_B





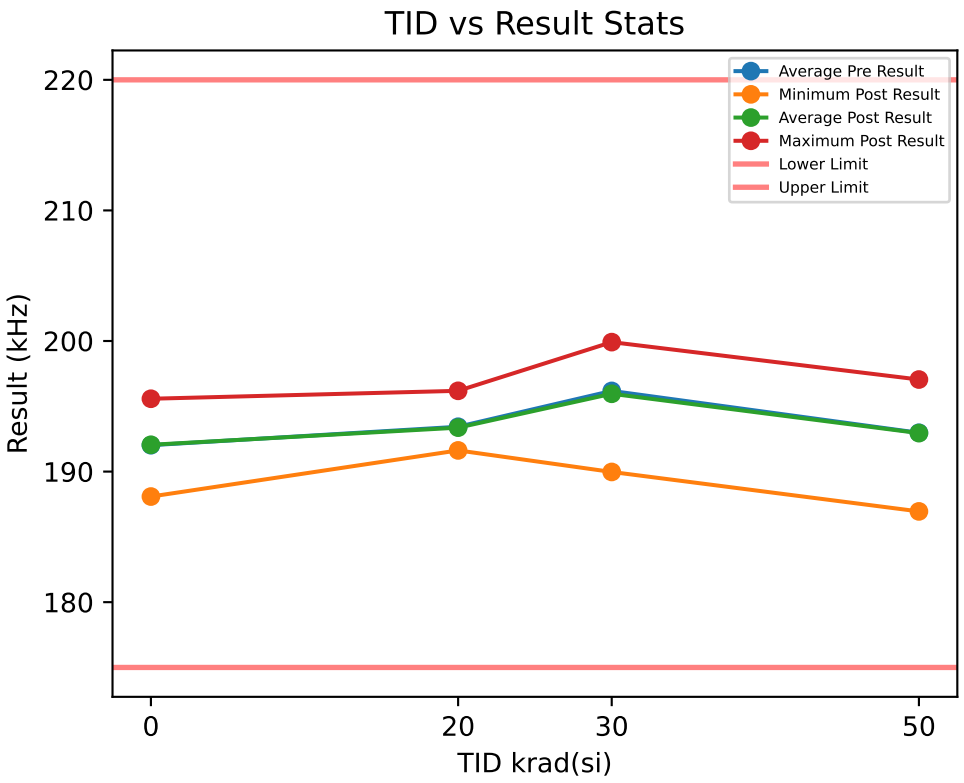
Test Results (Lower Limit = 175.0, Upper Limit = 220.0 (kHz))

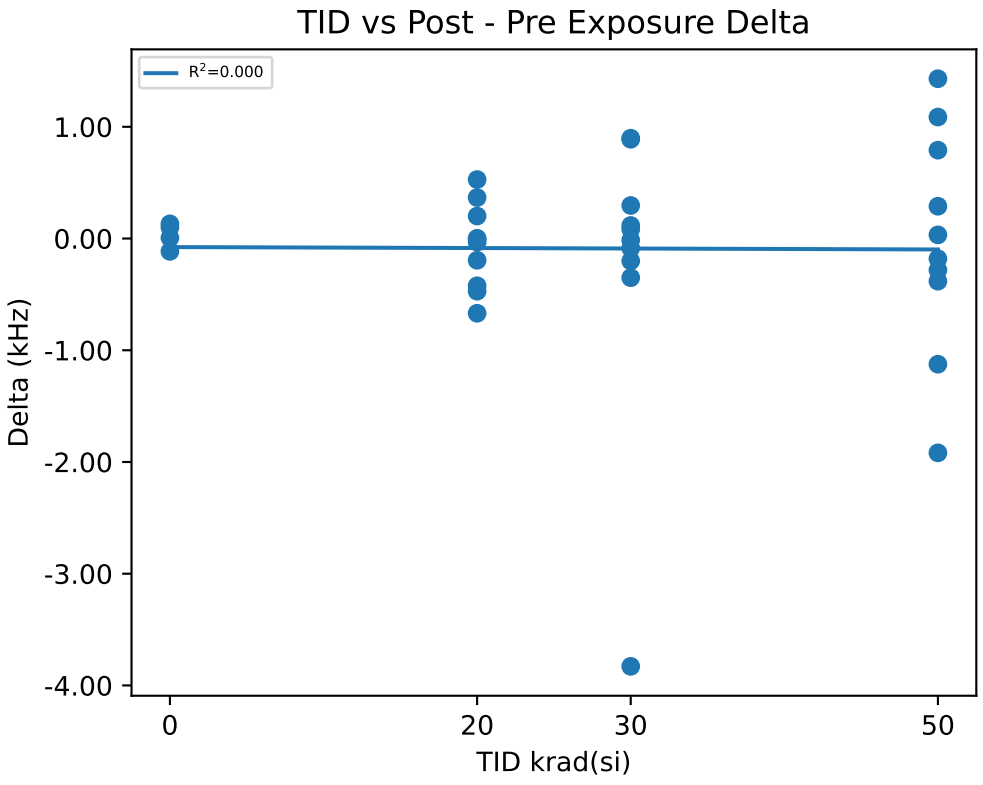
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	190.57	190.13	-0.4412
2	20	Unbiased	194.17	193.76	-0.4177
3	50	Biased	195.11	195.92	0.8047
4	30	Unbiased	197.24	197.05	-0.1907
5	50	Unbiased	188.89	186.97	-1.9152
6	30	Biased	193.34	194.29	0.9515
7	50	Biased	194.22	194.02	-0.203
8	30	Unbiased	195.12	195.16	0.0456
9	20	Unbiased	191.71	191.66	-0.047
10	50	Biased	195.95	196.23	0.2737
11	30	Biased	197.15	198.05	0.8958
12	0	Correlation	188.27	188.19	-0.0766
13	0	Correlation	191.88	191.89	0.0184
14	50	Unbiased	197.33	197.12	-0.2043
15	20	Biased	192.86	193.29	0.4246
16	20	Unbiased	191.78	192.31	0.5361
17	20	Biased	196.74	196.25	-0.4888
18	20	Unbiased	193.72	193.09	-0.6326
19	20	Biased	194.05	193.85	-0.2012
20	50	Unbiased	192.82	191.67	-1.1539
21	0	Correlation	192.72	192.79	0.0667
22	50	Unbiased	192.03	192.14	0.1105
23	0	Correlation	195.56	195.66	0.1064
24	20	Biased	194.08	194.15	0.0662
26	50	Biased	193.3	194.38	1.0781
27	30	Unbiased	192.16	192.19	0.0305
28	30	Biased	199.7	199.6	-0.1003
29	30	Unbiased	200.34	199.99	-0.3565
30	20	Biased	191.98	192.22	0.2424
31	30	Unbiased	198.39	198.48	0.0911
33	30	Biased	195.1	195.36	0.2608
34	50	Unbiased	190.1	191.53	1.4382
35	20	Unbiased	193.81	193.85	0.0366
41	30	Biased	193.89	190.03	-3.8633

Test Statistics (kHz)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	188.27	192.11	195.56	3.0037	188.19	192.13	195.66	3.0812	-0.0766	0.028725	0.1064	0.0789
20	191.71	193.49	196.74	1.5139	191.66	193.44	196.25	1.2866	-0.6326	-0.04814	0.5361	0.38948
30	192.16	196.24	200.34	2.7565	190.03	196.02	199.99	3.2401	-3.8633	-0.22355	0.9515	1.3493
50	188.89	193.03	197.33	2.7015	186.97	193.01	197.12	3.1282	-1.9152	-0.02124	1.4382	1.0131

Device Test: 20.83 LEVEL|FREQ/RT/12/12/0/1000/5/200kHz//@FSW_EXT_RT_B





Test Results (Lower Limit = 175.0, Upper Limit = 220.0 (kHz))

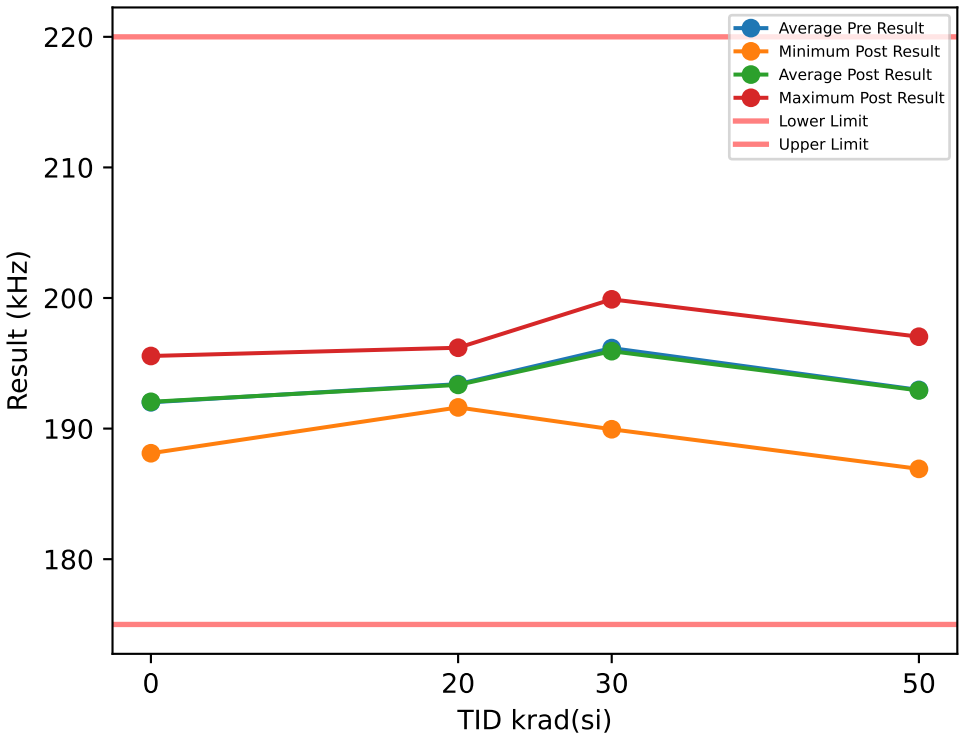
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	190.48	190.1	-0.3818
2	20	Unbiased	194.09	193.66	-0.4226
3	50	Biased	195.03	195.82	0.791
4	30	Unbiased	197.16	196.96	-0.2004
5	50	Unbiased	188.87	186.95	-1.9181
6	30	Biased	193.33	194.23	0.898
7	50	Biased	194.2	193.91	-0.282
8	30	Unbiased	195.11	195.1	-0.0146
9	20	Unbiased	191.65	191.62	-0.0324
10	50	Biased	195.89	196.17	0.2889
11	30	Biased	197.1	197.99	0.8886
12	0	Correlation	188.2	188.09	-0.1148
13	0	Correlation	191.78	191.79	0.0064
14	50	Unbiased	197.23	197.05	-0.1805
15	20	Biased	192.85	193.22	0.3669
16	20	Unbiased	191.73	192.26	0.5281
17	20	Biased	196.66	196.18	-0.4713
18	20	Unbiased	193.64	192.97	-0.6688
19	20	Biased	193.97	193.78	-0.1947
20	50	Unbiased	192.74	191.62	-1.1248
21	0	Correlation	192.62	192.75	0.1315
22	50	Unbiased	191.99	192.02	0.0328
23	0	Correlation	195.48	195.58	0.1005
24	20	Biased	194.07	194.07	-0.0043
26	50	Biased	193.26	194.35	1.0874
27	30	Unbiased	192.07	192.15	0.0825
28	30	Biased	199.6	199.51	-0.0857
29	30	Unbiased	200.26	199.91	-0.3504
30	20	Biased	191.93	192.13	0.2014
31	30	Unbiased	198.32	198.43	0.1167
33	30	Biased	195.02	195.31	0.2959
34	50	Unbiased	190.04	191.47	1.4303
35	20	Unbiased	193.74	193.74	0.0021
41	30	Biased	193.8	189.97	-3.8293

Test Statistics (kHz)

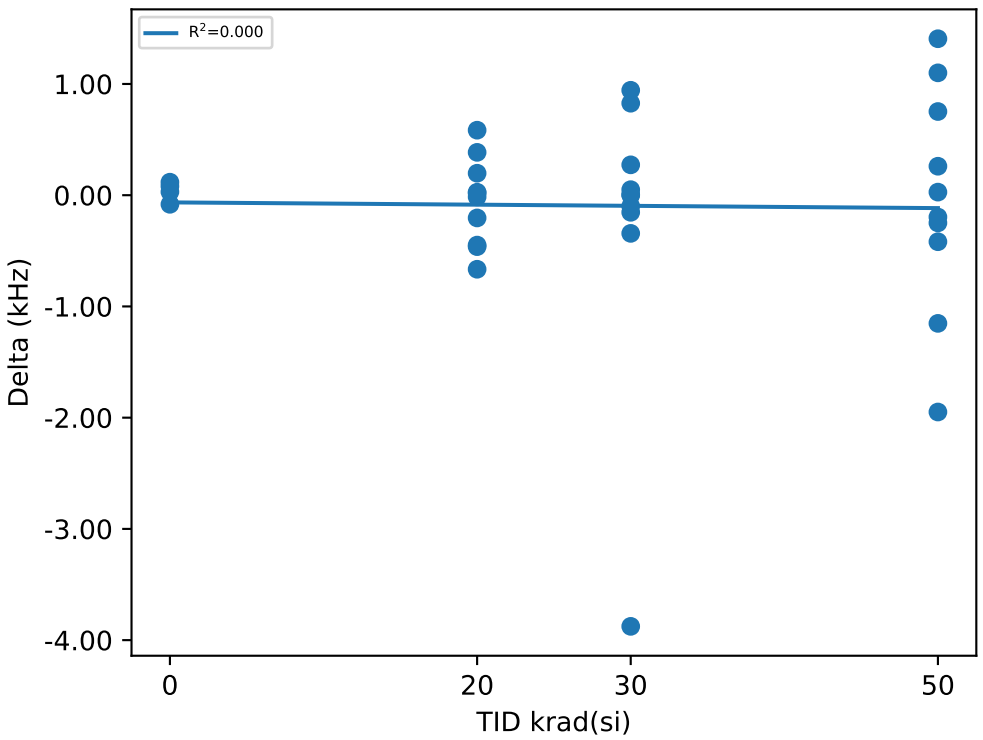
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	188.2	192.02	195.48	2.9961	188.09	192.05	195.58	3.0926	-0.1148	0.0309	0.1315	0.11074
20	191.65	193.43	196.66	1.5028	191.62	193.36	196.18	1.2831	-0.6688	-0.06956	0.5281	0.37899
30	192.07	196.18	200.26	2.7476	189.97	195.96	199.91	3.2328	-3.8293	-0.21987	0.898	1.3356
50	188.87	192.97	197.23	2.689	186.95	192.95	197.05	3.1139	-1.9181	-0.02568	1.4303	1.0074

Device Test: 20.85 LEVEL|FREQ/RT/14/14/0/1000/5/200kHz//@FSW_EXT_RT_B

TID vs Result Stats



TID vs Post - Pre Exposure Delta



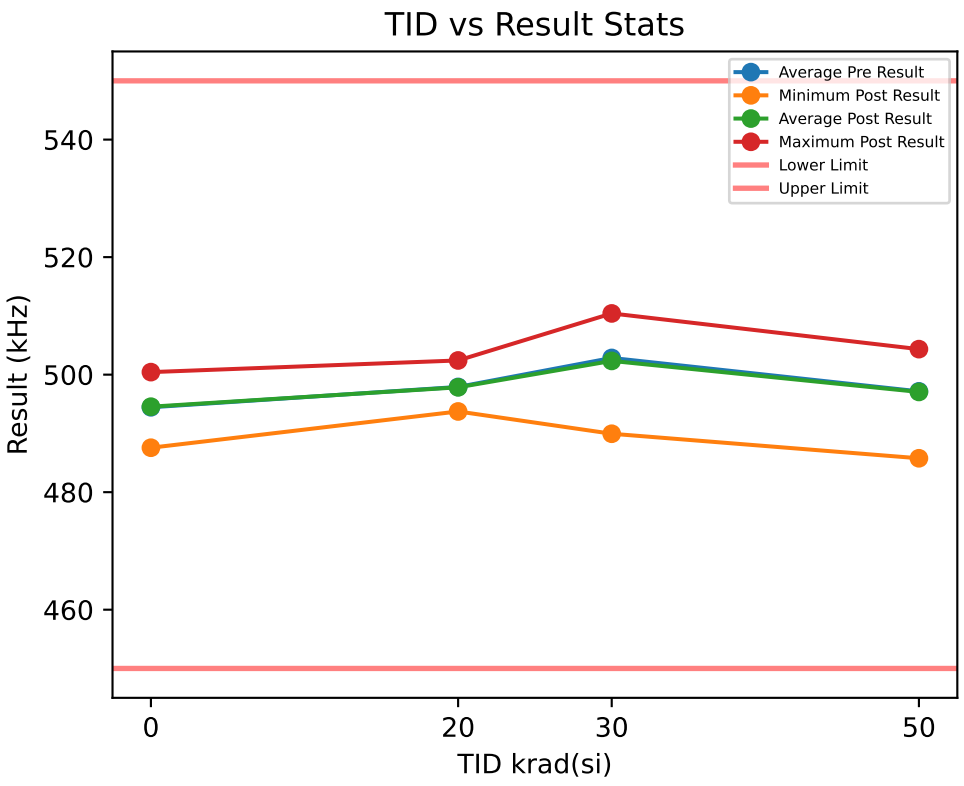
Test Results (Lower Limit = 175.0, Upper Limit = 220.0 (kHz))

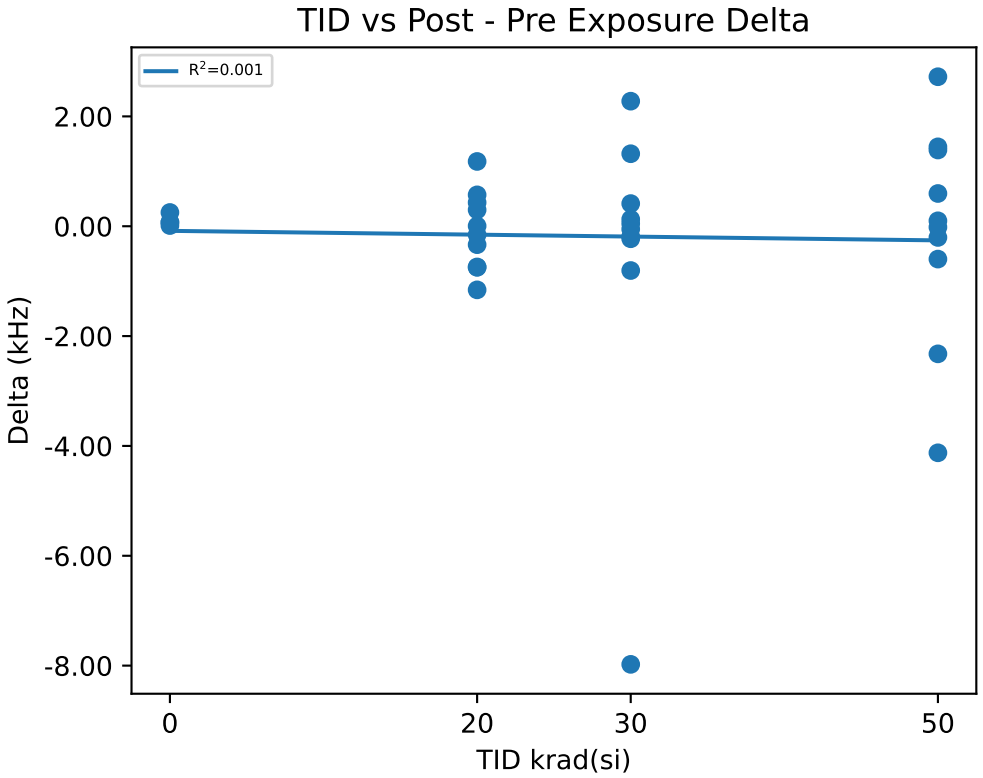
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	190.45	190.03	-0.4182
2	20	Unbiased	194.08	193.63	-0.4485
3	50	Biased	195.04	195.79	0.7523
4	30	Unbiased	197.13	196.98	-0.1537
5	50	Unbiased	188.86	186.91	-1.9491
6	30	Biased	193.27	194.21	0.9433
7	50	Biased	194.16	193.91	-0.249
8	30	Unbiased	195.07	195.08	0.0058
9	20	Unbiased	191.64	191.62	-0.0151
10	50	Biased	195.88	196.14	0.2604
11	30	Biased	197.07	197.9	0.8269
12	0	Correlation	188.19	188.11	-0.0818
13	0	Correlation	191.75	191.78	0.0303
14	50	Unbiased	197.23	197.04	-0.1961
15	20	Biased	192.81	193.19	0.3852
16	20	Unbiased	191.66	192.24	0.5844
17	20	Biased	196.65	196.19	-0.4624
18	20	Unbiased	193.65	192.98	-0.6657
19	20	Biased	193.94	193.74	-0.2044
20	50	Unbiased	192.72	191.57	-1.1523
21	0	Correlation	192.63	192.74	0.117
22	50	Unbiased	192.01	192.03	0.0277
23	0	Correlation	195.48	195.56	0.0812
24	20	Biased	194.01	194.03	0.0202
26	50	Biased	193.23	194.33	1.1
27	30	Unbiased	192.11	192.11	0.0002
28	30	Biased	199.59	199.49	-0.0978
29	30	Unbiased	200.24	199.9	-0.3432
30	20	Biased	191.92	192.12	0.1975
31	30	Unbiased	198.32	198.37	0.0497
33	30	Biased	195.01	195.29	0.273
34	50	Unbiased	190.04	191.44	1.4066
35	20	Unbiased	193.69	193.72	0.0265
41	30	Biased	193.82	189.95	-3.8761

Test Statistics (kHz)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	188.19	192.01	195.48	3.0021	188.11	192.05	195.56	3.0754	-0.0818	0.036675	0.117	0.086625
20	191.64	193.4	196.65	1.5101	191.62	193.35	196.19	1.2816	-0.6657	-0.05823	0.5844	0.39388
30	192.11	196.16	200.24	2.74	189.95	195.93	199.9	3.2286	-3.8761	-0.23719	0.9433	1.3443
50	188.86	192.96	197.23	2.6919	186.91	192.92	197.04	3.1223	-1.9491	-0.04177	1.4066	1.0115

Device Test: 20.87 LEVEL|FREQ/RT/4.5/4.5/0/1000/4.5/500kHz//@FSW_EXT_RT_C





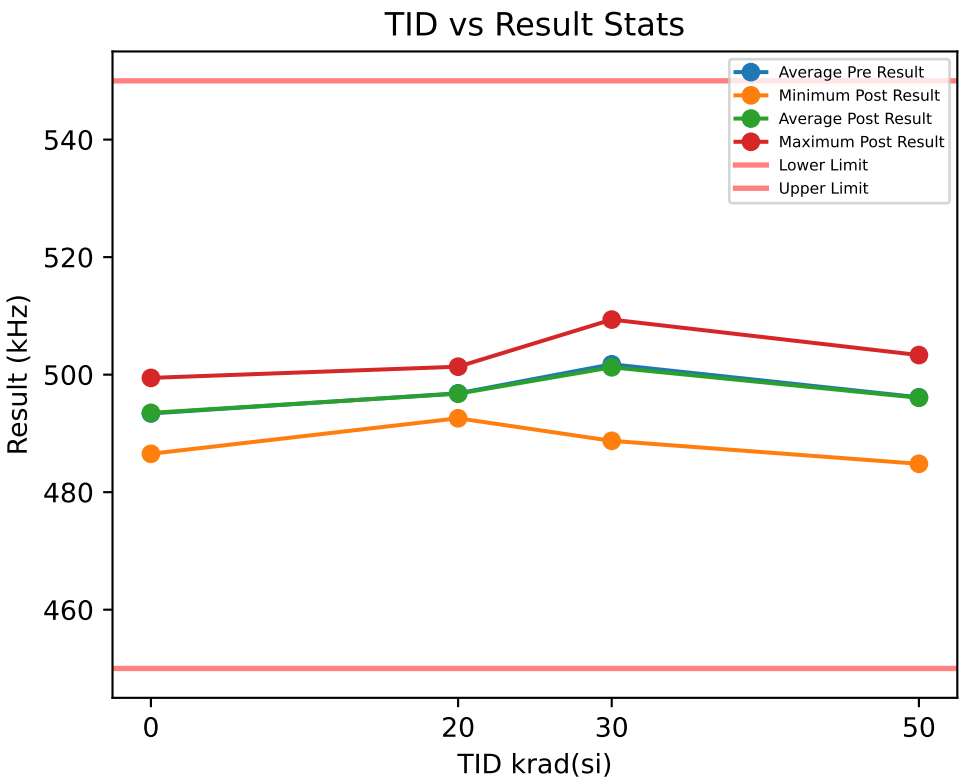
Test Results (Lower Limit = 450.0, Upper Limit = 550.0 (kHz))

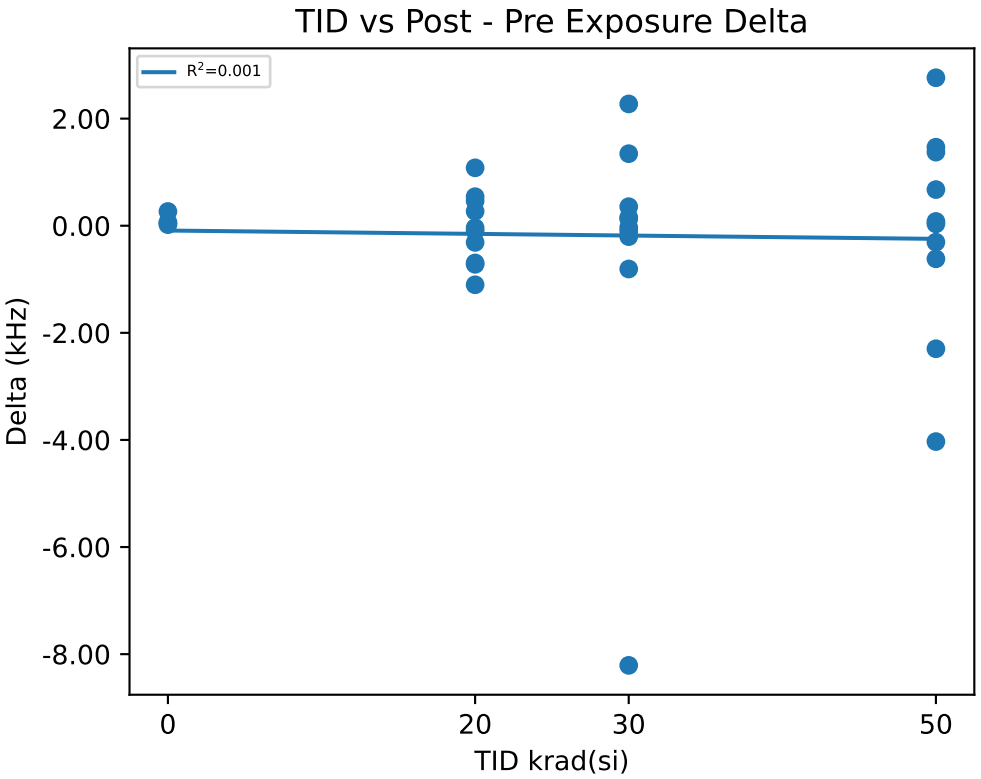
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	492.51	492.3	-0.2039
2	20	Unbiased	499.76	499.01	-0.7481
3	50	Biased	502.38	503.77	1.3881
4	30	Unbiased	505.6	505.41	-0.1855
5	50	Unbiased	489.89	485.77	-4.1251
6	30	Biased	497.63	499.91	2.277
7	50	Biased	499.28	499.26	-0.0173
8	30	Unbiased	499.68	499.63	-0.0523
9	20	Unbiased	495.38	495.04	-0.3356
10	50	Biased	501.95	502.54	0.5962
11	30	Biased	505.16	506.48	1.3202
12	0	Correlation	487.31	487.56	0.2507
13	0	Correlation	492.93	493	0.0703
14	50	Unbiased	504.94	504.34	-0.5981
15	20	Biased	497.06	497.49	0.4314
16	20	Unbiased	493.39	494.57	1.1796
17	20	Biased	503.16	502.42	-0.7414
18	20	Unbiased	497.26	496.1	-1.1582
19	20	Biased	501.17	501.01	-0.1555
20	50	Unbiased	495.99	493.67	-2.3235
21	0	Correlation	497.12	497.19	0.0747
22	50	Unbiased	494.73	494.83	0.0989
23	0	Correlation	500.42	500.43	0.0127
24	20	Biased	499.83	500.13	0.298
26	50	Biased	497.22	498.67	1.4455
27	30	Unbiased	495.52	495.29	-0.2279
28	30	Biased	507.67	507.8	0.1277
29	30	Unbiased	511.22	510.42	-0.8062
30	20	Biased	493.16	493.74	0.5715
31	30	Unbiased	506.74	506.79	0.0483
33	30	Biased	501.26	501.68	0.4126
34	50	Unbiased	492.69	495.41	2.722
35	20	Unbiased	498.92	498.93	0.0051
41	30	Biased	497.92	489.94	-7.977

Test Statistics (kHz)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	487.31	494.44	500.42	5.6565	487.56	494.55	500.43	5.5613	0.0127	0.1021	0.2507	0.10302
20	493.16	497.91	503.16	3.2801	493.74	497.84	502.42	2.9315	-1.1582	-0.06532	1.1796	0.71008
30	495.52	502.84	511.22	5.1563	489.94	502.34	510.42	6.3121	-7.977	-0.50631	2.277	2.7674
50	489.89	497.16	504.94	4.9081	485.77	497.06	504.34	5.8193	-4.1251	-0.10172	2.722	1.9579

Device Test: 20.89 LEVEL|FREQ/RT/5/5/0/1000/5/500kHz//@FSW_EXT_RT_C





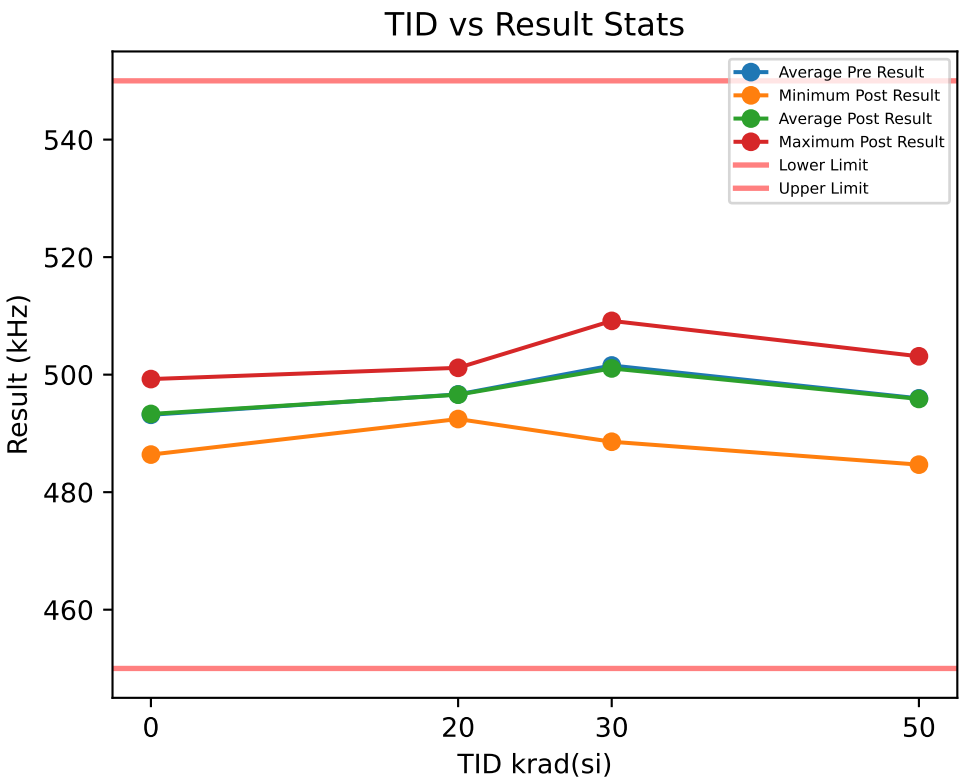
Test Results (Lower Limit = 450.0, Upper Limit = 550.0 (kHz))

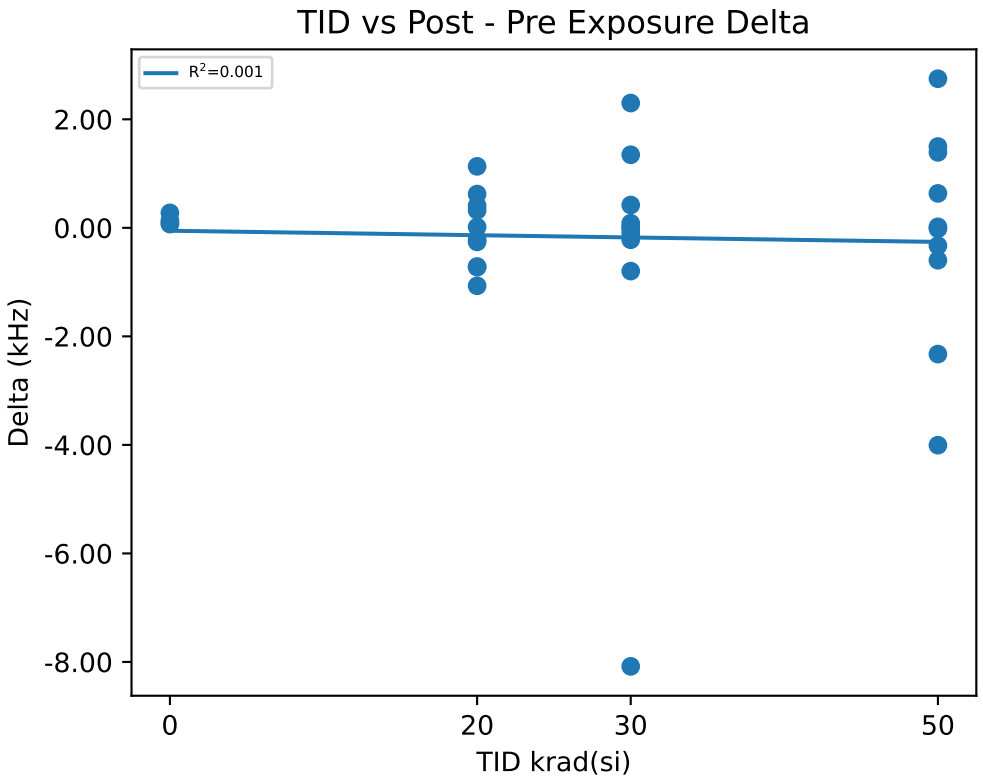
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	491.59	491.28	-0.3065
2	20	Unbiased	498.65	497.93	-0.7207
3	50	Biased	501.29	502.67	1.3741
4	30	Unbiased	504.5	504.4	-0.1009
5	50	Unbiased	488.86	484.83	-4.0305
6	30	Biased	496.56	498.83	2.2743
7	50	Biased	498.15	498.18	0.0344
8	30	Unbiased	498.54	498.51	-0.0311
9	20	Unbiased	494.23	493.92	-0.3117
10	50	Biased	500.93	501.61	0.6753
11	30	Biased	504.05	505.4	1.3454
12	0	Correlation	486.27	486.53	0.2658
13	0	Correlation	491.81	491.88	0.0663
14	50	Unbiased	503.95	503.33	-0.6181
15	20	Biased	495.84	496.3	0.4629
16	20	Unbiased	492.48	493.57	1.0812
17	20	Biased	502.05	501.35	-0.6947
18	20	Unbiased	496.18	495.08	-1.1026
19	20	Biased	500.15	500.05	-0.0974
20	50	Unbiased	495.05	492.76	-2.2973
21	0	Correlation	496.06	496.11	0.0466
22	50	Unbiased	493.76	493.84	0.0802
23	0	Correlation	499.43	499.45	0.0202
24	20	Biased	498.68	498.95	0.2702
26	50	Biased	496.17	497.64	1.4665
27	30	Unbiased	494.4	494.19	-0.2035
28	30	Biased	506.57	506.73	0.158
29	30	Unbiased	510.18	509.37	-0.8079
30	20	Biased	492.03	492.58	0.5426
31	30	Unbiased	505.51	505.63	0.1253
33	30	Biased	500.36	500.72	0.3554
34	50	Unbiased	491.72	494.48	2.7634
35	20	Unbiased	497.94	497.91	-0.0381
41	30	Biased	496.94	488.74	-8.2091

Test Statistics (kHz)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	486.27	493.39	499.43	5.6814	486.53	493.49	499.45	5.5788	0.0202	0.099725	0.2658	0.11232
20	492.03	496.82	502.05	3.2699	492.58	496.76	501.35	2.9476	-1.1026	-0.06083	1.0812	0.66995
30	494.4	501.76	510.18	5.1376	488.74	501.25	509.37	6.3447	-8.2091	-0.50941	2.2743	2.8411
50	488.86	496.15	503.95	4.884	484.83	496.06	503.33	5.7891	-4.0305	-0.08585	2.7634	1.9455

Device Test: 20.91 LEVEL|FREQ/RT/12/12/0/1000/5/500kHz//@FSW_EXT_RT_C





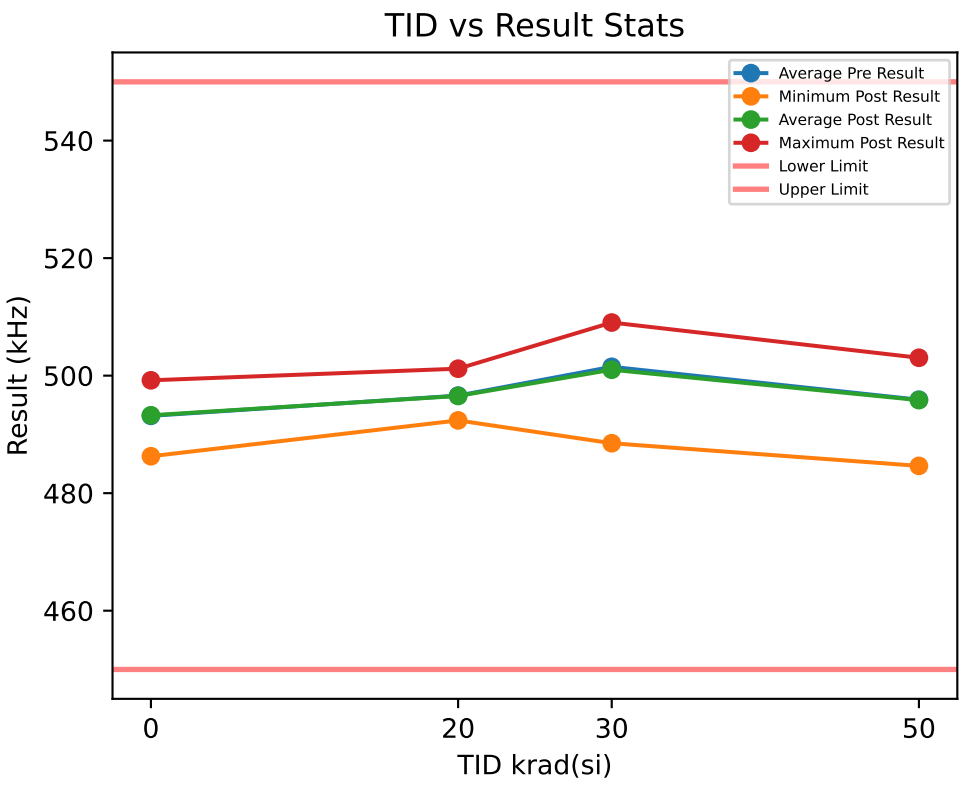
Test Results (Lower Limit = 450.0, Upper Limit = 550.0 (kHz))

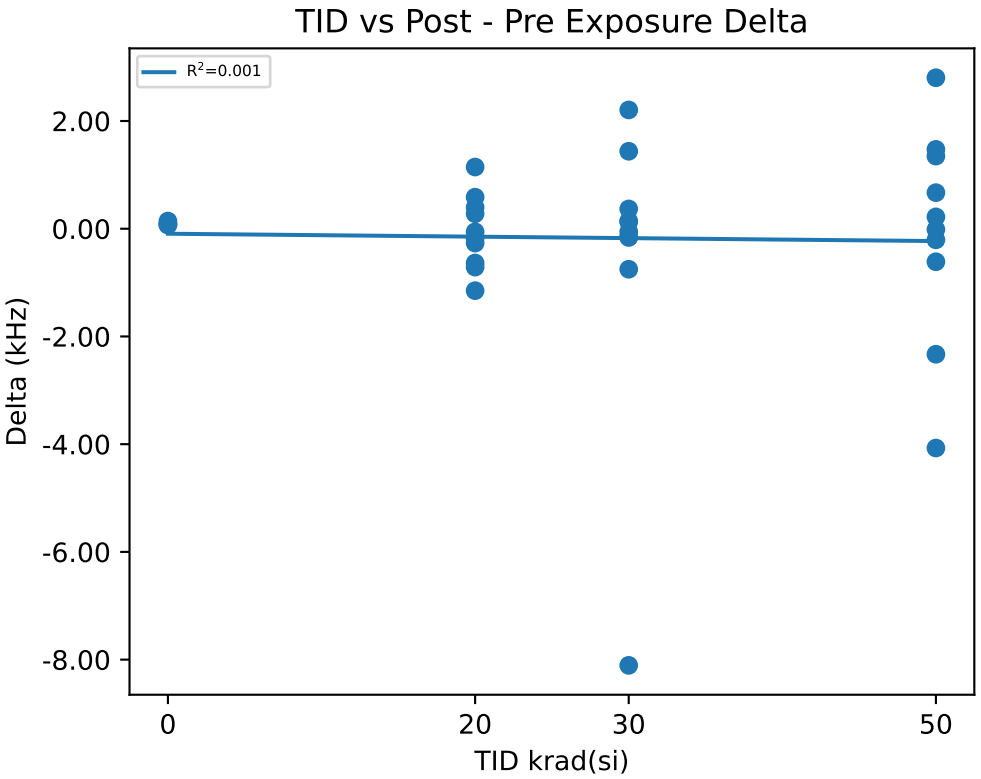
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	491.4	491.07	-0.3283
2	20	Unbiased	498.43	497.72	-0.7125
3	50	Biased	501.09	502.48	1.3907
4	30	Unbiased	504.37	504.27	-0.0981
5	50	Unbiased	488.69	484.68	-4.0049
6	30	Biased	496.33	498.63	2.2998
7	50	Biased	498.02	498	-0.0159
8	30	Unbiased	498.34	498.33	-0.0118
9	20	Unbiased	494.02	493.76	-0.2589
10	50	Biased	500.76	501.39	0.6349
11	30	Biased	503.83	505.18	1.3467
12	0	Correlation	486.12	486.4	0.2759
13	0	Correlation	491.52	491.66	0.1367
14	50	Unbiased	503.72	503.12	-0.5968
15	20	Biased	495.71	496.12	0.4082
16	20	Unbiased	492.3	493.43	1.1331
17	20	Biased	501.89	501.16	-0.724
18	20	Unbiased	496.01	494.94	-1.0683
19	20	Biased	500.02	499.8	-0.2203
20	50	Unbiased	494.85	492.52	-2.3266
21	0	Correlation	495.87	495.94	0.0693
22	50	Unbiased	493.61	493.63	0.0183
23	0	Correlation	499.16	499.25	0.087
24	20	Biased	498.47	498.79	0.3225
26	50	Biased	495.97	497.47	1.4987
27	30	Unbiased	494.25	494.03	-0.2197
28	30	Biased	506.39	506.47	0.0851
29	30	Unbiased	509.95	509.15	-0.7974
30	20	Biased	491.82	492.45	0.6226
31	30	Unbiased	505.38	505.4	0.0157
33	30	Biased	500.11	500.53	0.4206
34	50	Unbiased	491.53	494.28	2.7476
35	20	Unbiased	497.74	497.76	0.0154
41	30	Biased	496.66	488.58	-8.0811

Test Statistics (kHz)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	486.12	493.17	499.16	5.6443	486.4	493.31	499.25	5.5582	0.0693	0.14223	0.2759	0.093572
20	491.82	496.64	501.89	3.2814	492.45	496.59	501.16	2.921	-1.0683	-0.04822	1.1331	0.68377
30	494.25	501.56	509.95	5.1478	488.58	501.06	509.15	6.3205	-8.0811	-0.50402	2.2998	2.8037
50	488.69	495.96	503.72	4.8736	484.68	495.87	503.12	5.7812	-4.0049	-0.09823	2.7476	1.9423

Device Test: 20.93 LEVEL|FREQ/RT/14/14/0/1000/5/500kHz//@FSW_EXT_RT_C





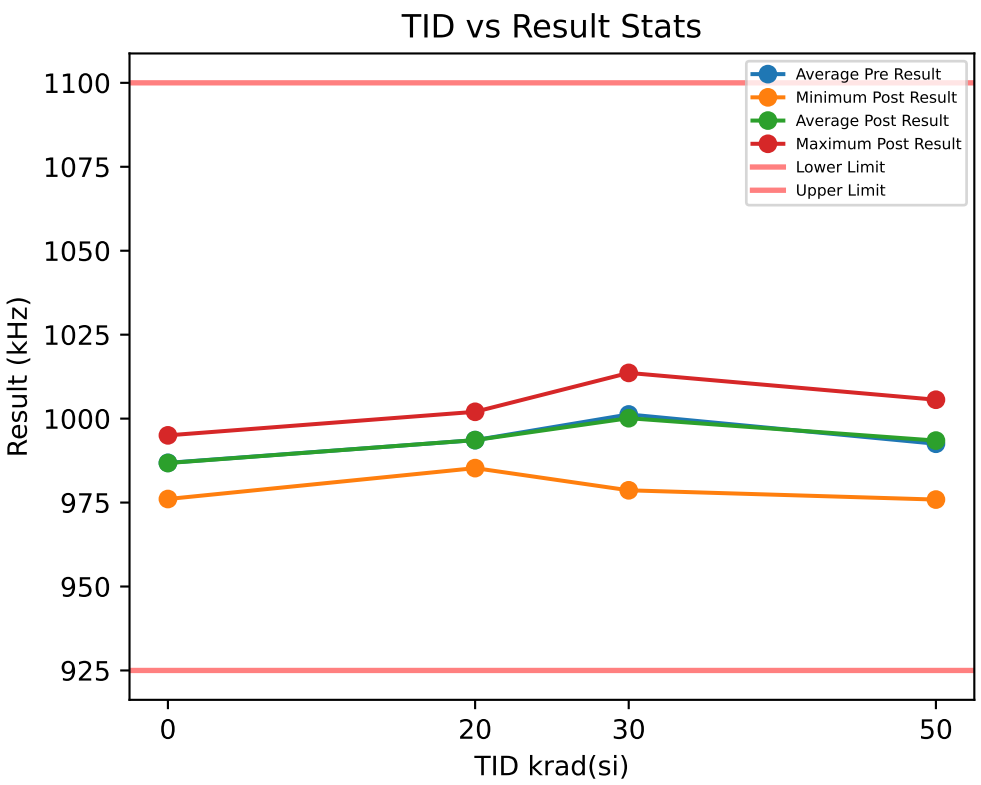
Test Results (Lower Limit = 450.0, Upper Limit = 550.0 (kHz))

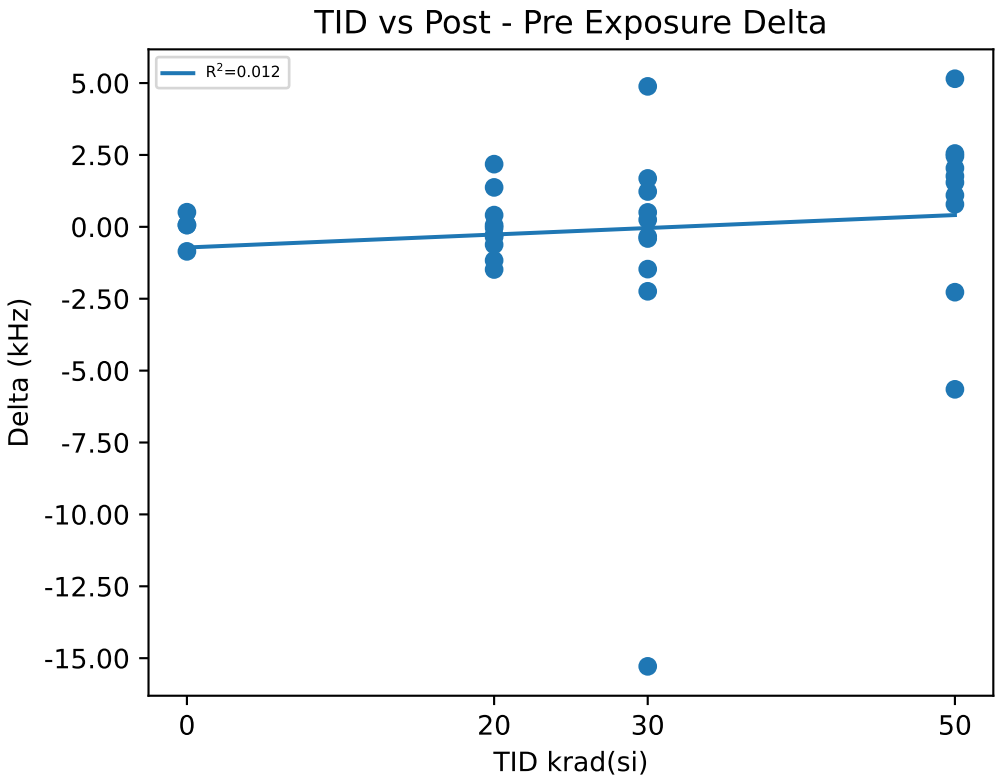
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	491.28	491.08	-0.2057
2	20	Unbiased	498.41	497.7	-0.7125
3	50	Biased	501.09	502.44	1.3485
4	30	Unbiased	504.29	504.12	-0.1619
5	50	Unbiased	488.71	484.64	-4.0714
6	30	Biased	496.41	498.61	2.2053
7	50	Biased	497.89	497.88	-0.0136
8	30	Unbiased	498.37	498.31	-0.0541
9	20	Unbiased	493.97	493.71	-0.2668
10	50	Biased	500.72	501.39	0.6698
11	30	Biased	503.68	505.11	1.4381
12	0	Correlation	486.14	486.28	0.1426
13	0	Correlation	491.55	491.64	0.0897
14	50	Unbiased	503.65	503.04	-0.6129
15	20	Biased	495.72	496.11	0.3971
16	20	Unbiased	492.22	493.37	1.1453
17	20	Biased	501.82	501.18	-0.636
18	20	Unbiased	495.99	494.84	-1.1496
19	20	Biased	499.93	499.75	-0.1794
20	50	Unbiased	494.8	492.47	-2.3303
21	0	Correlation	495.82	495.89	0.0675
22	50	Unbiased	493.49	493.71	0.22
23	0	Correlation	499.12	499.21	0.0826
24	20	Biased	498.46	498.74	0.2784
26	50	Biased	496	497.47	1.4733
27	30	Unbiased	494.14	493.99	-0.1512
28	30	Biased	506.3	506.44	0.1431
29	30	Unbiased	509.79	509.04	-0.7524
30	20	Biased	491.8	492.38	0.5858
31	30	Unbiased	505.32	505.45	0.128
33	30	Biased	500.12	500.49	0.3673
34	50	Unbiased	491.44	494.24	2.8032
35	20	Unbiased	497.72	497.66	-0.0573
41	30	Biased	496.61	488.5	-8.1063

Test Statistics (kHz)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	486.14	493.16	499.12	5.6127	486.28	493.25	499.21	5.5847	0.0675	0.0956	0.1426	0.032672
20	491.8	496.6	501.82	3.2757	492.38	496.54	501.18	2.9389	-1.1496	-0.0595	1.1453	0.68273
30	494.14	501.5	509.79	5.1067	488.5	501.01	509.04	6.319	-8.1063	-0.49441	2.2053	2.8085
50	488.71	495.91	503.65	4.8788	484.64	495.84	503.04	5.7694	-4.0714	-0.07191	2.8032	1.964

Device Test: 20.95 LEVEL|FREQ/RT/4.5/4.5/0/1000/4.5/1MHz//@FSW_EXT_RT_D





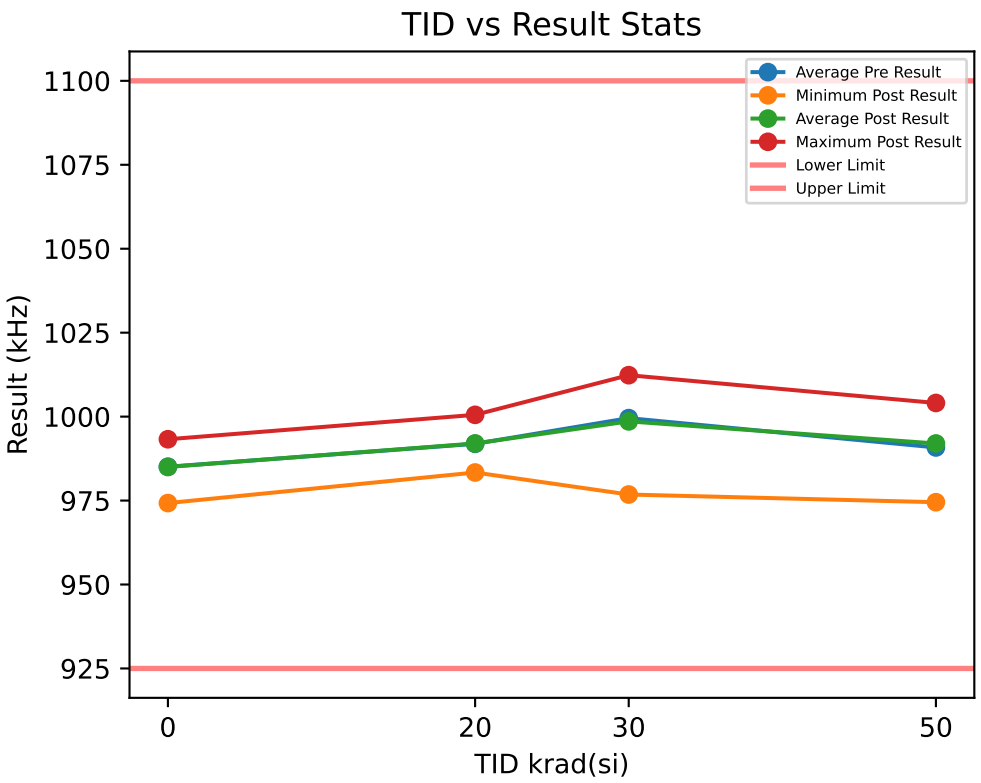
Test Results (Lower Limit = 925.0, Upper Limit = 1100.0 (kHz))

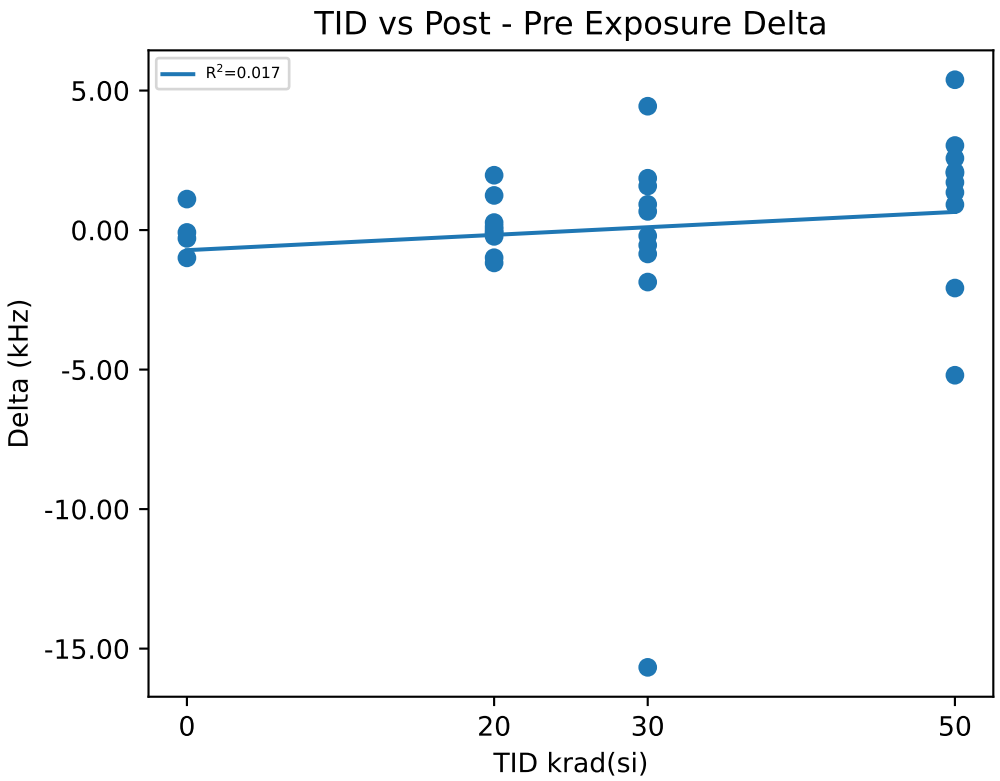
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	985.08	986.18	1.0983
2	20	Unbiased	996.67	996.4	-0.2742
3	50	Biased	1003	1005.1	2.0416
4	30	Unbiased	1007.6	1007.3	-0.3419
5	50	Unbiased	981.54	975.89	-5.6507
6	30	Biased	992.84	997.73	4.8846
7	50	Biased	995.47	997.02	1.5423
8	30	Unbiased	995.43	993.19	-2.2417
9	20	Unbiased	989.83	991.2	1.3713
10	50	Biased	999.13	1000.9	1.7639
11	30	Biased	1005.8	1007.5	1.6841
12	0	Correlation	976	976.06	0.061
13	0	Correlation	982.67	983.18	0.5088
14	50	Unbiased	1004.8	1005.6	0.7824
15	20	Biased	993.57	993.22	-0.3489
16	20	Unbiased	985.81	986.21	0.4084
17	20	Biased	1000.8	999.34	-1.4839
18	20	Unbiased	990.63	989.47	-1.1679
19	20	Biased	1002.1	1002	-0.0292
20	50	Unbiased	989.94	987.67	-2.2729
21	0	Correlation	993.69	992.84	-0.8532
22	50	Unbiased	987.61	990.07	2.4583
23	0	Correlation	994.95	995.02	0.0649
24	20	Biased	998.13	997.51	-0.6211
26	50	Biased	991.61	994.16	2.5506
27	30	Unbiased	989.83	990.08	0.2477
28	30	Biased	1006.6	1007.8	1.2283
29	30	Unbiased	1015.1	1013.6	-1.4702
30	20	Biased	983.08	985.26	2.1799
31	30	Unbiased	1006.7	1006.3	-0.406
33	30	Biased	998.61	999.11	0.5029
34	50	Unbiased	986.9	992.05	5.1503
35	20	Unbiased	995.33	995.39	0.0611
41	30	Biased	993.94	978.65	-15.284

Test Statistics (kHz)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	976	986.83	994.95	9.0864	976.06	986.77	995.02	8.8027	-0.8532	-0.054625	0.5088	0.57237
20	983.08	993.59	1002.1	6.2462	985.26	993.6	1002	5.5521	-1.4839	0.00955	2.1799	1.1031
30	989.83	1001.2	1015.1	8.2057	978.65	1000.1	1013.6	10.547	-15.284	-1.1197	4.8846	5.3444
50	981.54	992.51	1004.8	7.8426	975.89	993.46	1005.6	9.1873	-5.6507	0.94641	5.1503	2.9569

Device Test: 20.97 LEVEL|FREQ/RT/5/5/0/1000/5/1MHz//@FSW_EXT_RT_D





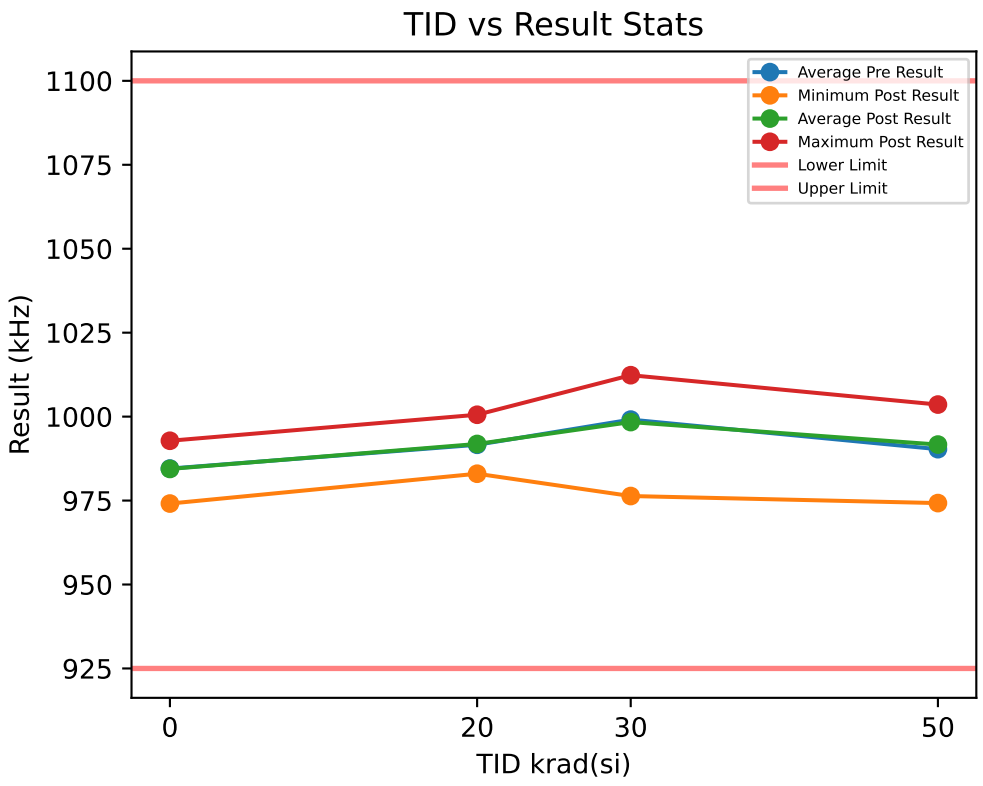
Test Results (Lower Limit = 925.0, Upper Limit = 1100.0 (kHz))

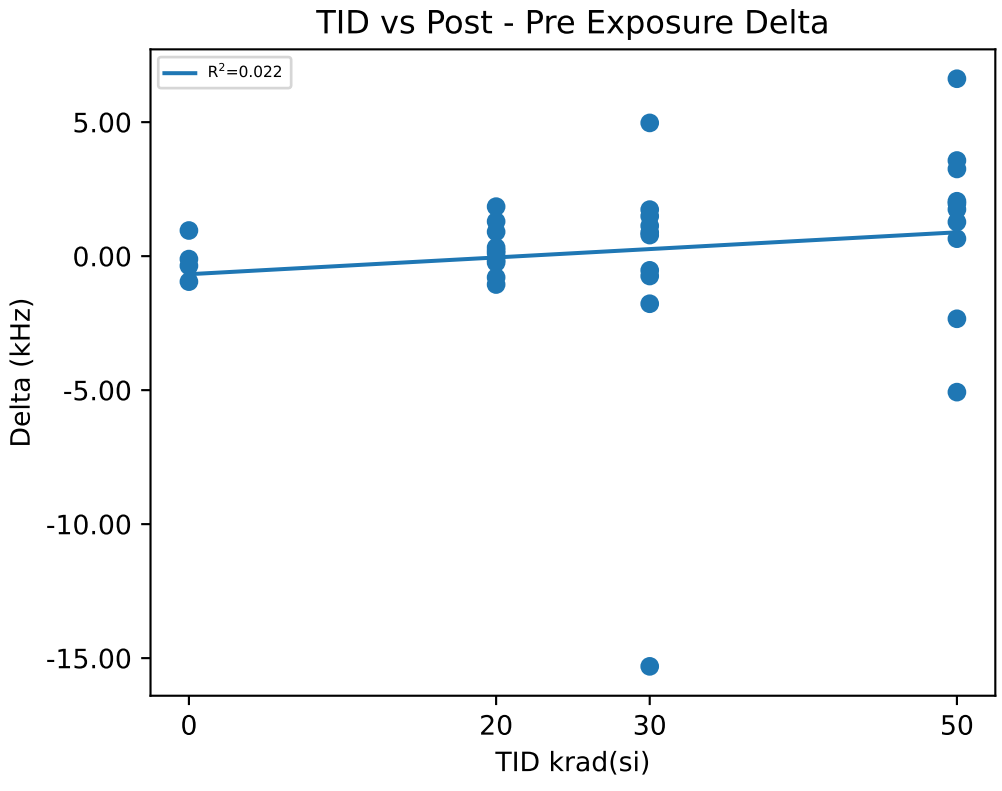
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	983.52	984.87	1.349
2	20	Unbiased	995.13	995.01	-0.114
3	50	Biased	1001.2	1003.3	2.0906
4	30	Unbiased	1005.9	1005.7	-0.2083
5	50	Unbiased	979.71	974.51	-5.2027
6	30	Biased	991.32	995.76	4.4388
7	50	Biased	993.81	995.52	1.7093
8	30	Unbiased	993.51	991.65	-1.8631
9	20	Unbiased	988.01	989.26	1.2417
10	50	Biased	997.21	999.25	2.0413
11	30	Biased	1004.2	1006	1.8575
12	0	Correlation	974.34	974.25	-0.0842
13	0	Correlation	980.4	981.51	1.1108
14	50	Unbiased	1003.2	1004.1	0.9114
15	20	Biased	991.58	991.7	0.1249
16	20	Unbiased	984.37	984.64	0.2694
17	20	Biased	999.01	997.84	-1.1771
18	20	Unbiased	988.98	987.99	-0.9905
19	20	Biased	1000.5	1000.5	0.0232
20	50	Unbiased	988.39	986.31	-2.0778
21	0	Correlation	991.99	990.99	-0.9963
22	50	Unbiased	985.96	988.54	2.5748
23	0	Correlation	993.56	993.26	-0.2982
24	20	Biased	996.24	996.01	-0.2255
26	50	Biased	989.92	992.95	3.0307
27	30	Unbiased	988.02	988.69	0.6693
28	30	Biased	1004.9	1006.5	1.5788
29	30	Unbiased	1013.2	1012.3	-0.8556
30	20	Biased	981.39	983.36	1.9656
31	30	Unbiased	1005	1004.4	-0.5431
33	30	Biased	996.97	997.89	0.9208
34	50	Unbiased	985.33	990.72	5.3877
35	20	Unbiased	993.78	993.71	-0.0717
41	30	Biased	992.47	976.8	-15.672

Test Statistics (kHz)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	974.34	985.07	993.56	9.2539	974.25	985.01	993.26	8.79	-0.9963	-0.066975	1.1108	0.87646
20	981.39	991.9	1000.5	6.2207	983.36	992	1000.5	5.6517	-1.1771	0.1046	1.9656	0.93216
30	988.02	999.55	1013.2	8.1693	976.8	998.58	1012.3	10.655	-15.672	-0.96765	4.4388	5.454
50	979.71	990.82	1003.2	7.7929	974.51	992	1004.1	9.0764	-5.2027	1.1814	5.3877	2.9132

Device Test: 20.99 LEVEL|FREQ/RT/12/12/0/1000/5/1MHz//@FSW_EXT_RT_D





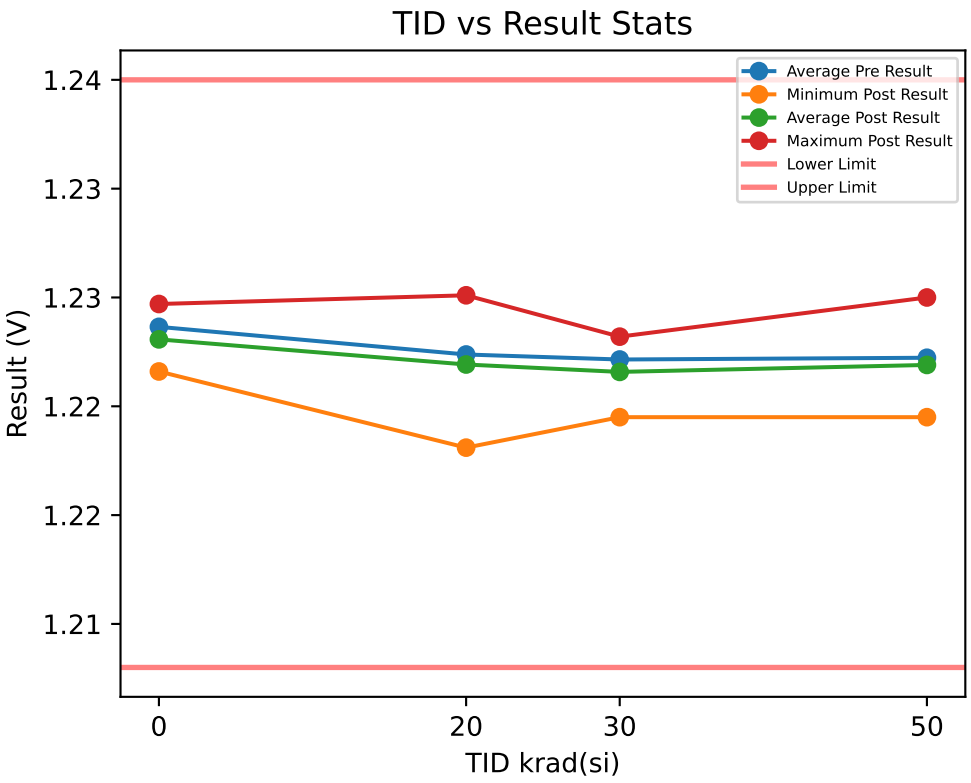
Test Results (Lower Limit = 925.0, Upper Limit = 1100.0 (kHz))

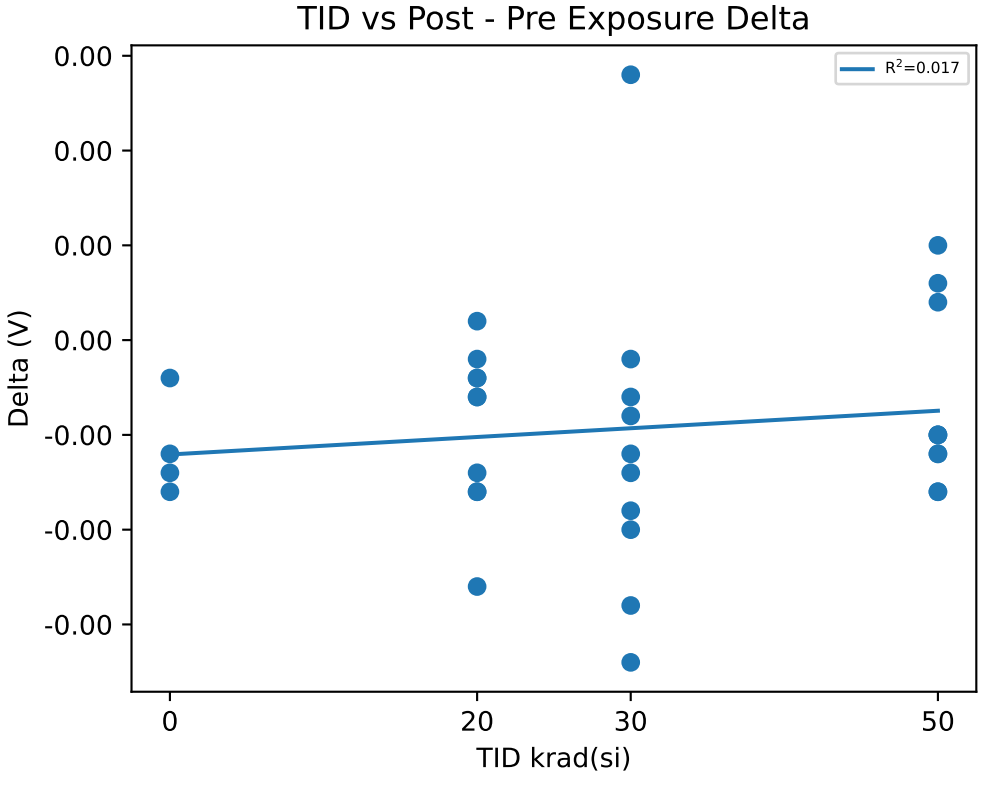
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	983.16	984.91	1.7437
2	20	Unbiased	995	994.85	-0.1511
3	50	Biased	1001	1003	2.0488
4	30	Unbiased	1004.6	1005.5	0.883
5	50	Unbiased	979.32	974.25	-5.0742
6	30	Biased	990.76	995.73	4.9716
7	50	Biased	993.65	994.92	1.2748
8	30	Unbiased	993.2	991.43	-1.7758
9	20	Unbiased	987.58	988.87	1.295
10	50	Biased	995.68	999.25	3.5687
11	30	Biased	1004	1005.8	1.7363
12	0	Correlation	974.22	974.11	-0.1095
13	0	Correlation	979.13	980.08	0.9572
14	50	Unbiased	1002.9	1003.6	0.6516
15	20	Biased	991.26	991.58	0.3252
16	20	Unbiased	983.56	984.47	0.9077
17	20	Biased	998.84	997.78	-1.0591
18	20	Unbiased	988.77	987.97	-0.7937
19	20	Biased	1000.3	1000.6	0.2093
20	50	Unbiased	987.99	985.65	-2.3373
21	0	Correlation	991.62	990.67	-0.9513
22	50	Unbiased	986.03	987.99	1.9638
23	0	Correlation	993.17	992.81	-0.3605
24	20	Biased	996.1	995.86	-0.2408
26	50	Biased	989.44	992.7	3.2537
27	30	Unbiased	987.73	988.51	0.7856
28	30	Biased	1004.7	1006.2	1.4918
29	30	Unbiased	1012.9	1012.3	-0.5291
30	20	Biased	981.15	982.99	1.8472
31	30	Unbiased	1004.9	1004.2	-0.7417
33	30	Biased	996.63	997.76	1.1312
34	50	Unbiased	983.87	990.49	6.62
35	20	Unbiased	993.51	993.62	0.1112
41	30	Biased	991.66	976.35	-15.307

Test Statistics (kHz)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	974.22	984.53	993.17	9.3179	974.11	984.42	992.81	8.8426	-0.9513	-0.11603	0.9572	0.79777
20	981.15	991.61	1000.3	6.3478	982.99	991.86	1000.6	5.7358	-1.0591	0.24509	1.8472	0.90104
30	987.73	999.11	1012.9	8.1973	976.35	998.38	1012.3	10.714	-15.307	-0.7354	4.9716	5.4315
50	979.32	990.31	1002.9	7.8236	974.25	991.68	1003.6	9.0699	-5.0742	1.3714	6.62	3.2093

Device Test: 21.1 VOLTAGE|VREF/VREF/4.5/4.5/0/0/4.5/100kHz//@V_REFCAP





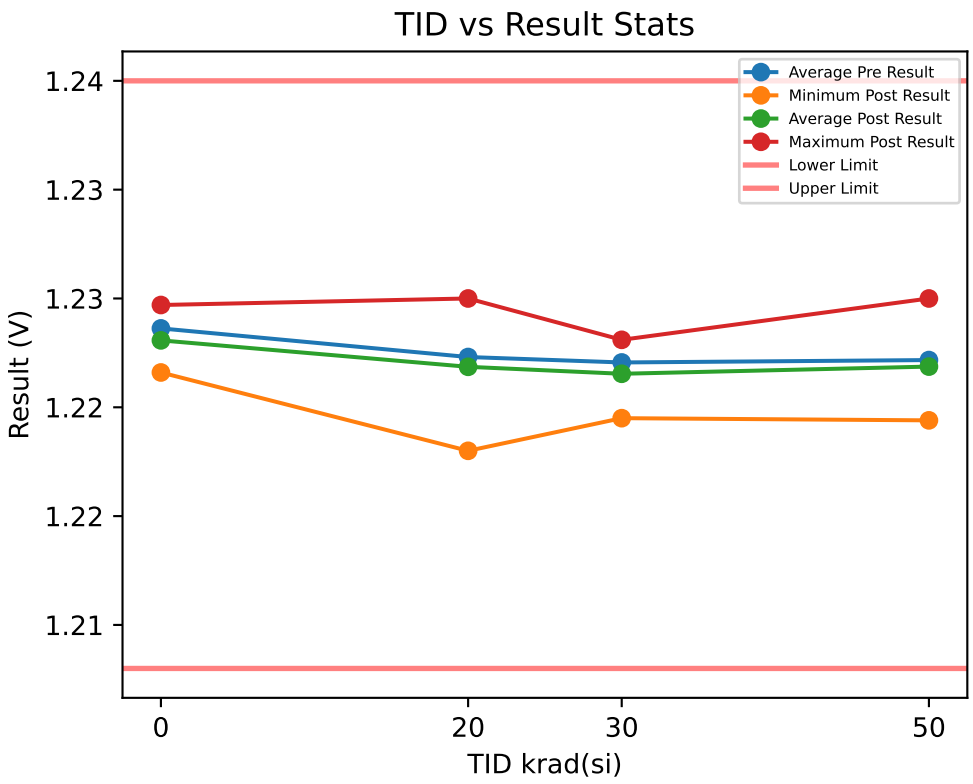
Test Results (Lower Limit = 1.208, Upper Limit = 1.235 (V))

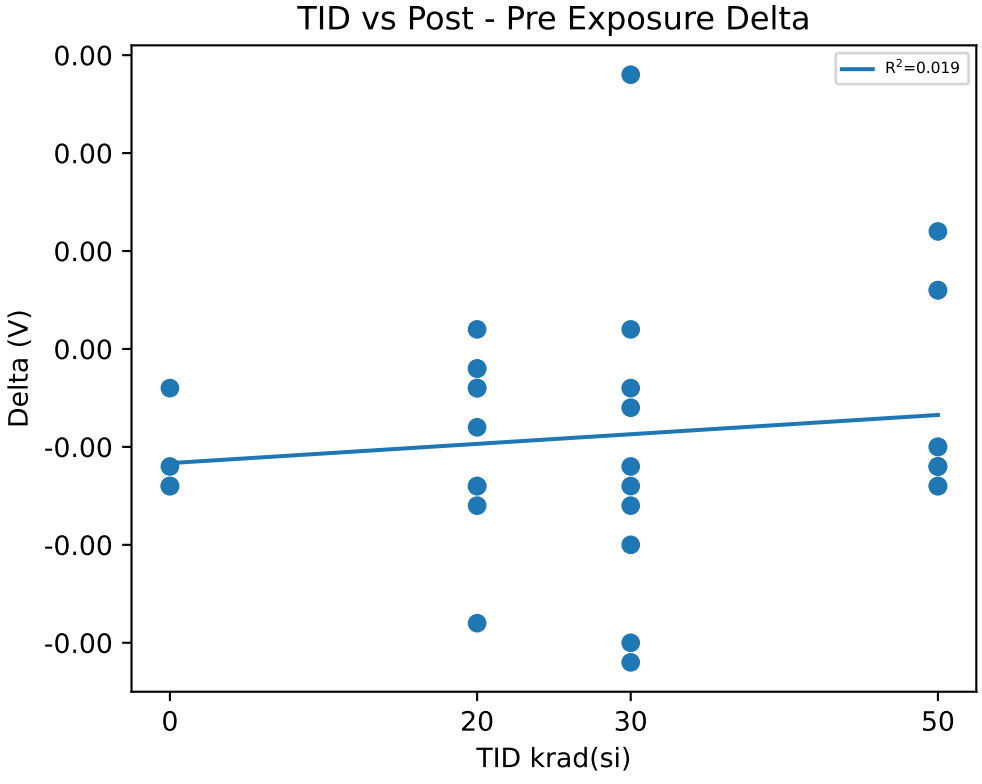
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	1.2218	1.2212	-0.0006
2	20	Unbiased	1.2236	1.2235	-0.0001
3	50	Biased	1.2248	1.224	-0.0008
4	30	Unbiased	1.2222	1.2212	-0.001
5	50	Unbiased	1.2204	1.2198	-0.0006
6	30	Biased	1.2213	1.2207	-0.0006
7	50	Biased	1.2221	1.2213	-0.0008
8	30	Unbiased	1.2212	1.2195	-0.0017
9	20	Unbiased	1.2205	1.2202	-0.0003
10	50	Biased	1.22	1.2195	-0.0005
11	30	Biased	1.2217	1.2213	-0.0004
12	0	Correlation	1.2236	1.223	-0.0006
13	0	Correlation	1.2254	1.2247	-0.0007
14	50	Unbiased	1.2203	1.2198	-0.0005
15	20	Biased	1.2205	1.2202	-0.0003
16	20	Unbiased	1.225	1.2242	-0.0008
17	20	Biased	1.2216	1.2209	-0.0007
18	20	Unbiased	1.2244	1.2231	-0.0013
19	20	Biased	1.2216	1.2214	-0.0002
20	50	Unbiased	1.2251	1.2246	-0.0005
21	0	Correlation	1.2224	1.2216	-0.0008
22	50	Unbiased	1.2245	1.225	0.0005
23	0	Correlation	1.2232	1.223	-0.0002
24	20	Biased	1.2233	1.2225	-0.0008
26	50	Biased	1.2206	1.2208	0.0002
27	30	Unbiased	1.2214	1.2213	-0.0001
28	30	Biased	1.2246	1.2232	-0.0014
29	30	Unbiased	1.2239	1.223	-0.0009
30	20	Biased	1.218	1.2181	0.0001
31	30	Unbiased	1.2211	1.2208	-0.0003
33	30	Biased	1.2235	1.2228	-0.0007
34	50	Unbiased	1.2227	1.223	0.0003
35	20	Unbiased	1.2253	1.2251	-0.0002
41	30	Biased	1.2206	1.222	0.0014

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2224	1.2237	1.2254	0.0012689	1.2216	1.2231	1.2247	0.0012685	-0.0008	-0.000575	-0.0002	0.000263
20	1.218	1.2224	1.2253	0.0023399	1.2181	1.2219	1.2251	0.0021436	-0.0013	-0.00046	0.0001	0.00042479
30	1.2206	1.2222	1.2246	0.0013657	1.2195	1.2216	1.2232	0.0011698	-0.0017	-0.00057	0.0014	0.00084859
50	1.22	1.2222	1.2251	0.0019754	1.2195	1.2219	1.225	0.0020859	-0.0008	-0.00033	0.0005	0.00047621

Device Test: 21.11 VOLTAGE|VREF/VREF/5/5/0/0/5/500kHz//@V_REFCAP





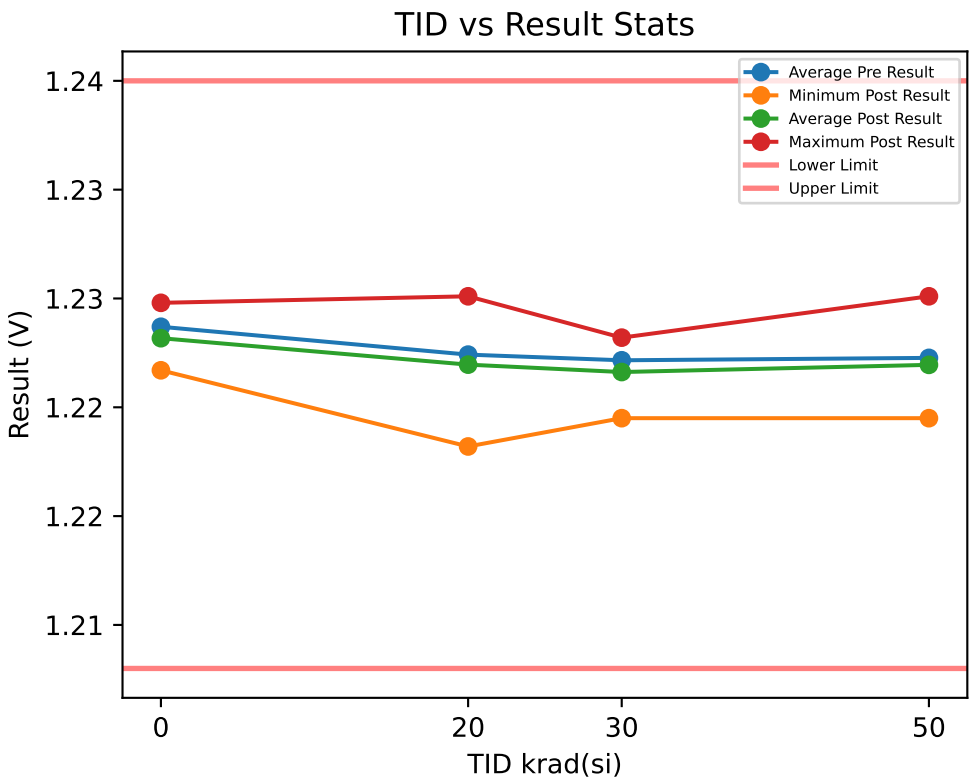
Test Results (Lower Limit = 1.208, Upper Limit = 1.235 (V))

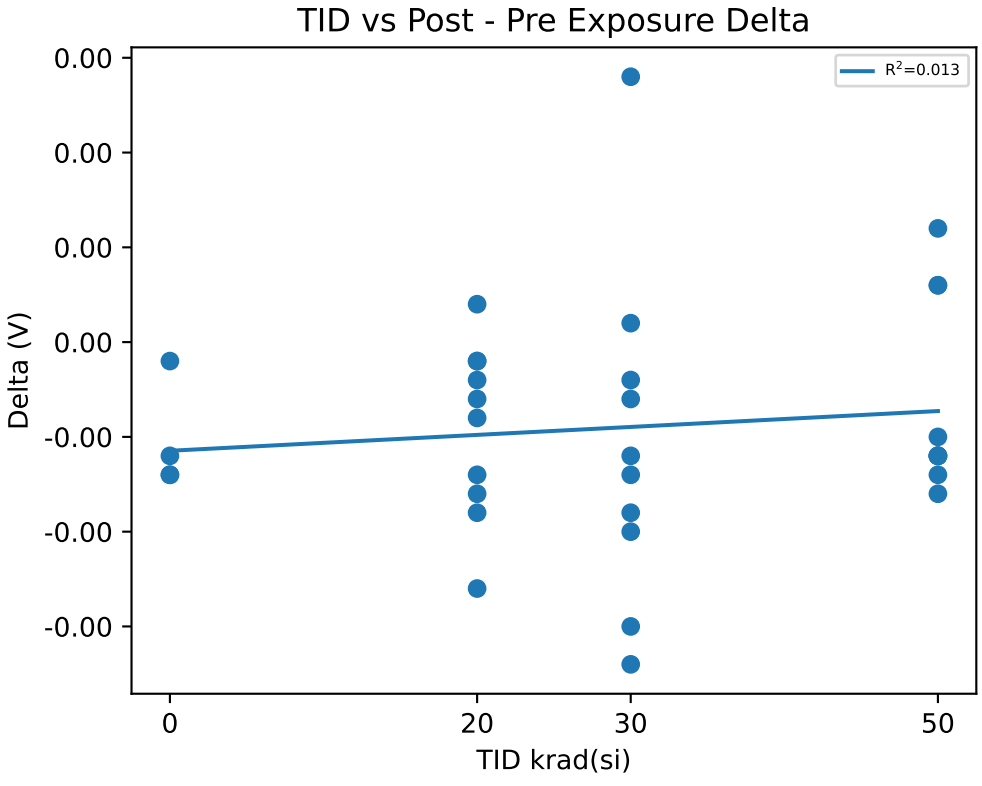
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	1.2218	1.2212	-0.0006
2	20	Unbiased	1.2235	1.2234	-0.0001
3	50	Biased	1.2247	1.224	-0.0007
4	30	Unbiased	1.2221	1.2211	-0.001
5	50	Unbiased	1.2203	1.2197	-0.0006
6	30	Biased	1.2212	1.2206	-0.0006
7	50	Biased	1.222	1.2213	-0.0007
8	30	Unbiased	1.2211	1.2195	-0.0016
9	20	Unbiased	1.2205	1.2201	-0.0004
10	50	Biased	1.2199	1.2194	-0.0005
11	30	Biased	1.2216	1.2213	-0.0003
12	0	Correlation	1.2236	1.223	-0.0006
13	0	Correlation	1.2254	1.2247	-0.0007
14	50	Unbiased	1.2203	1.2197	-0.0006
15	20	Biased	1.2203	1.2201	-0.0002
16	20	Unbiased	1.2249	1.2242	-0.0007
17	20	Biased	1.2216	1.2209	-0.0007
18	20	Unbiased	1.2244	1.223	-0.0014
19	20	Biased	1.2215	1.2214	-0.0001
20	50	Unbiased	1.2251	1.2246	-0.0005
21	0	Correlation	1.2223	1.2216	-0.0007
22	50	Unbiased	1.2244	1.225	0.0006
23	0	Correlation	1.2232	1.223	-0.0002
24	20	Biased	1.2233	1.2225	-0.0008
26	50	Biased	1.2205	1.2208	0.0003
27	30	Unbiased	1.2212	1.2213	0.0001
28	30	Biased	1.2246	1.2231	-0.0015
29	30	Unbiased	1.2238	1.223	-0.0008
30	20	Biased	1.2179	1.218	0.0001
31	30	Unbiased	1.221	1.2208	-0.0002
33	30	Biased	1.2235	1.2228	-0.0007
34	50	Unbiased	1.2227	1.223	0.0003
35	20	Unbiased	1.2252	1.225	-0.0002
41	30	Biased	1.2205	1.2219	0.0014

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2223	1.2236	1.2254	0.0013022	1.2216	1.2231	1.2247	0.0012685	-0.0007	-0.00055	-0.0002	0.00023805
20	1.2179	1.2223	1.2252	0.0023511	1.218	1.2219	1.225	0.0021511	-0.0014	-0.00045	0.0001	0.00045031
30	1.2205	1.2221	1.2246	0.0014033	1.2195	1.2215	1.2231	0.0011635	-0.0016	-0.00052	0.0014	0.00086255
50	1.2199	1.2222	1.2251	0.0019816	1.2194	1.2219	1.225	0.0021213	-0.0007	-0.0003	0.0006	0.00049441

Device Test: 21.13 VOLTAGE|VREF/VREF/12/12/0/0/5/500kHz//@V_REFCAP





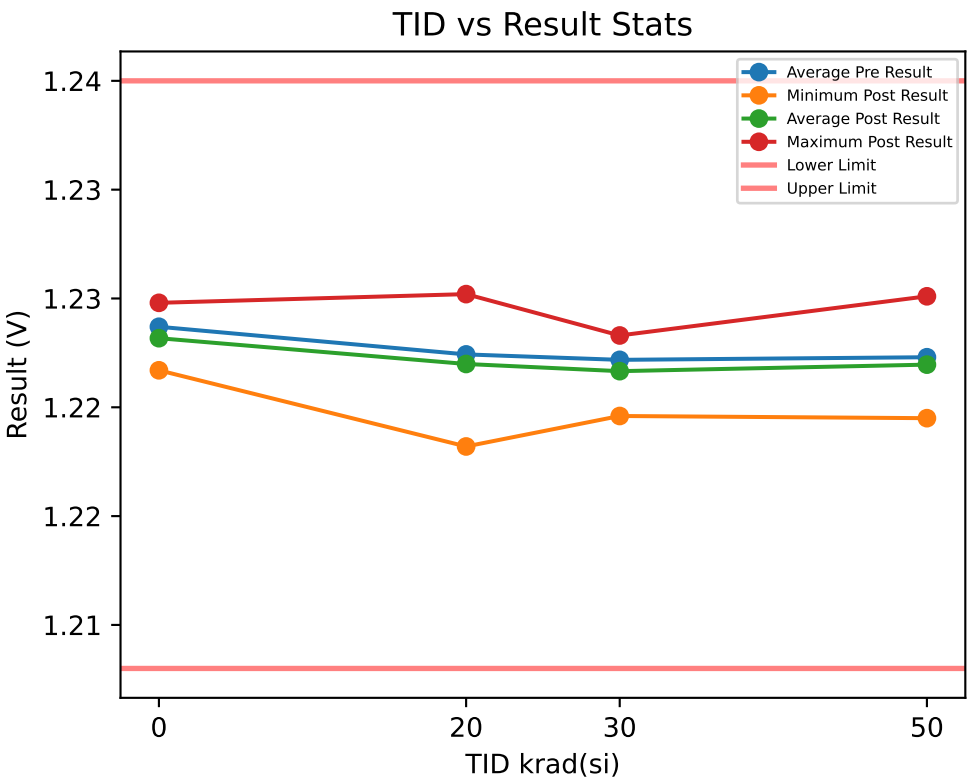
Test Results (Lower Limit = 1.208, Upper Limit = 1.235 (V))

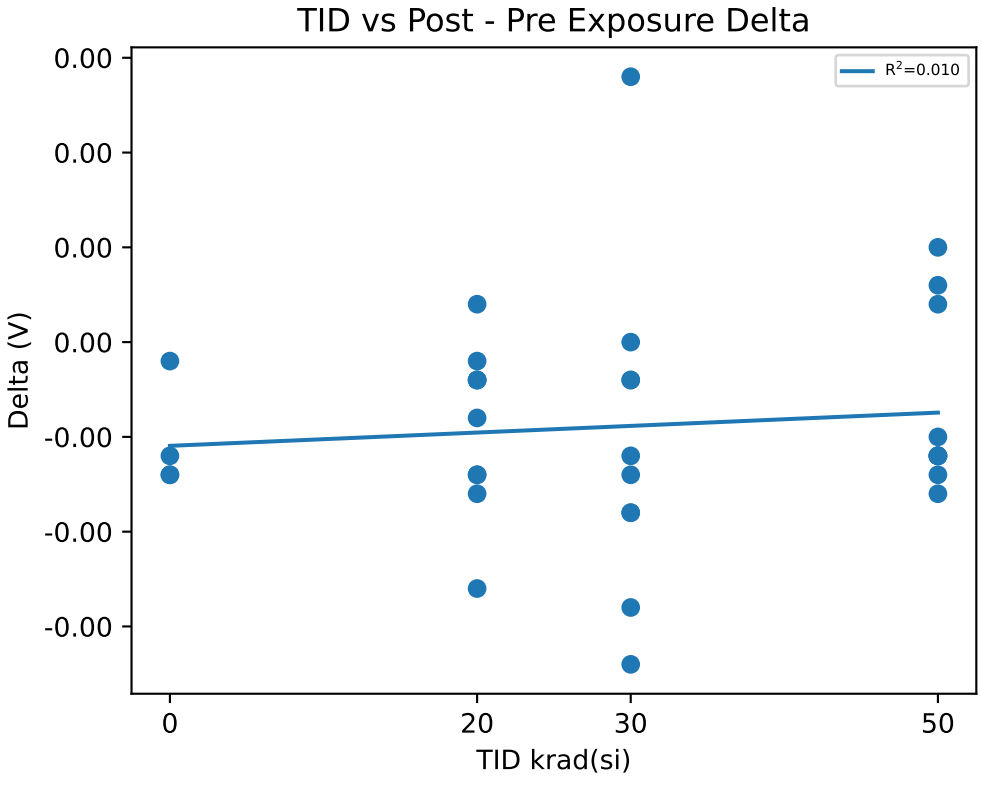
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	1.2219	1.2213	-0.0006
2	20	Unbiased	1.2236	1.2235	-0.0001
3	50	Biased	1.2248	1.224	-0.0008
4	30	Unbiased	1.2222	1.2212	-0.001
5	50	Unbiased	1.2204	1.2198	-0.0006
6	30	Biased	1.2213	1.2207	-0.0006
7	50	Biased	1.2221	1.2214	-0.0007
8	30	Unbiased	1.2212	1.2195	-0.0017
9	20	Unbiased	1.2206	1.2202	-0.0004
10	50	Biased	1.22	1.2195	-0.0005
11	30	Biased	1.2217	1.2214	-0.0003
12	0	Correlation	1.2237	1.2231	-0.0006
13	0	Correlation	1.2255	1.2248	-0.0007
14	50	Unbiased	1.2204	1.2198	-0.0006
15	20	Biased	1.2204	1.2202	-0.0002
16	20	Unbiased	1.225	1.2242	-0.0008
17	20	Biased	1.2217	1.221	-0.0007
18	20	Unbiased	1.2245	1.2232	-0.0013
19	20	Biased	1.2216	1.2215	-0.0001
20	50	Unbiased	1.2252	1.2246	-0.0006
21	0	Correlation	1.2224	1.2217	-0.0007
22	50	Unbiased	1.2245	1.2251	0.0006
23	0	Correlation	1.2232	1.2231	-0.0001
24	20	Biased	1.2234	1.2225	-0.0009
26	50	Biased	1.2206	1.2209	0.0003
27	30	Unbiased	1.2213	1.2214	0.0001
28	30	Biased	1.2247	1.2232	-0.0015
29	30	Unbiased	1.2239	1.223	-0.0009
30	20	Biased	1.218	1.2182	0.0002
31	30	Unbiased	1.2211	1.2209	-0.0002
33	30	Biased	1.2236	1.2229	-0.0007
34	50	Unbiased	1.2228	1.2231	0.0003
35	20	Unbiased	1.2254	1.2251	-0.0003
41	30	Biased	1.2206	1.222	0.0014

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2224	1.2237	1.2255	0.001314	1.2217	1.2232	1.2248	0.0012685	-0.0007	-0.000525	-0.0001	0.00028723
20	1.218	1.2224	1.2254	0.0023649	1.2182	1.222	1.2251	0.0021225	-0.0013	-0.00046	0.0002	0.00045509
30	1.2206	1.2222	1.2247	0.0014033	1.2195	1.2216	1.2232	0.0011698	-0.0017	-0.00054	0.0014	0.00088091
50	1.22	1.2223	1.2252	0.0019816	1.2195	1.222	1.2251	0.0020962	-0.0008	-0.00032	0.0006	0.00050947

Device Test: 21.15 VOLTAGE|VREF/VREF/14/14/0/0/5/500kHz//@V_REFCAP





Test Results (Lower Limit = 1.208, Upper Limit = 1.235 (V))

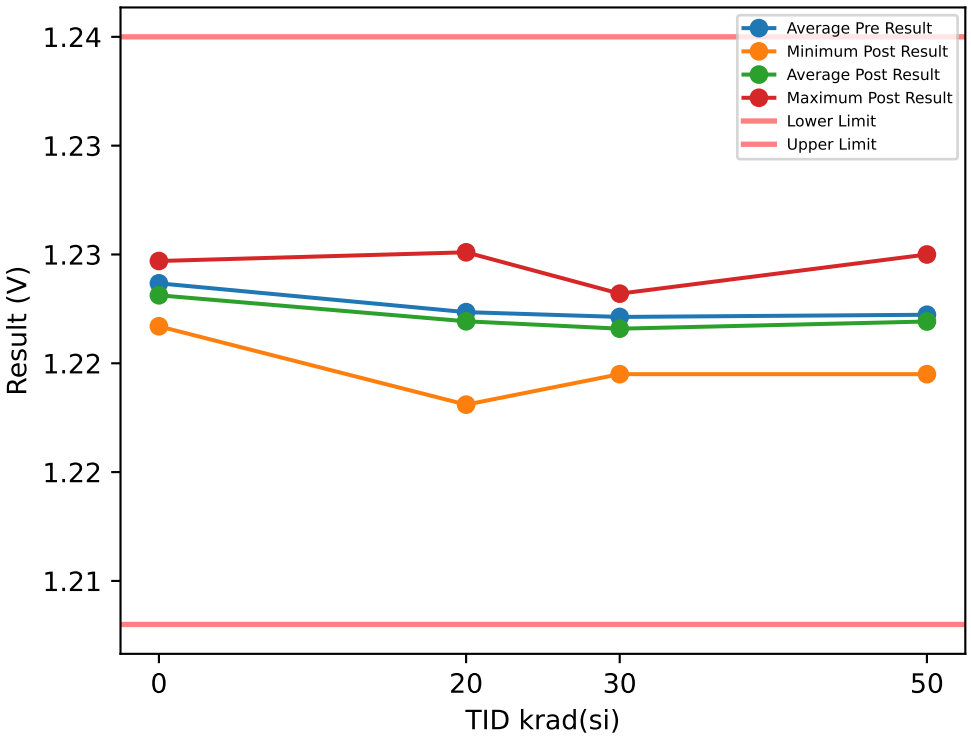
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	1.2219	1.2213	-0.0006
2	20	Unbiased	1.2237	1.2235	-0.0002
3	50	Biased	1.2248	1.224	-0.0008
4	30	Unbiased	1.2222	1.2213	-0.0009
5	50	Unbiased	1.2204	1.2198	-0.0006
6	30	Biased	1.2213	1.2207	-0.0006
7	50	Biased	1.2221	1.2214	-0.0007
8	30	Unbiased	1.2213	1.2196	-0.0017
9	20	Unbiased	1.2206	1.2202	-0.0004
10	50	Biased	1.2201	1.2195	-0.0006
11	30	Biased	1.2217	1.2215	-0.0002
12	0	Correlation	1.2237	1.2231	-0.0006
13	0	Correlation	1.2255	1.2248	-0.0007
14	50	Unbiased	1.2204	1.2198	-0.0006
15	20	Biased	1.2204	1.2202	-0.0002
16	20	Unbiased	1.2251	1.2243	-0.0008
17	20	Biased	1.2217	1.221	-0.0007
18	20	Unbiased	1.2245	1.2232	-0.0013
19	20	Biased	1.2216	1.2215	-0.0001
20	50	Unbiased	1.2252	1.2247	-0.0005
21	0	Correlation	1.2224	1.2217	-0.0007
22	50	Unbiased	1.2246	1.2251	0.0005
23	0	Correlation	1.2232	1.2231	-0.0001
24	20	Biased	1.2233	1.2226	-0.0007
26	50	Biased	1.2207	1.2209	0.0002
27	30	Unbiased	1.2214	1.2214	0
28	30	Biased	1.2247	1.2233	-0.0014
29	30	Unbiased	1.2239	1.223	-0.0009
30	20	Biased	1.218	1.2182	0.0002
31	30	Unbiased	1.2211	1.2209	-0.0002
33	30	Biased	1.2236	1.2229	-0.0007
34	50	Unbiased	1.2228	1.2231	0.0003
35	20	Unbiased	1.2254	1.2252	-0.0002
41	30	Biased	1.2206	1.222	0.0014

Test Statistics (V)

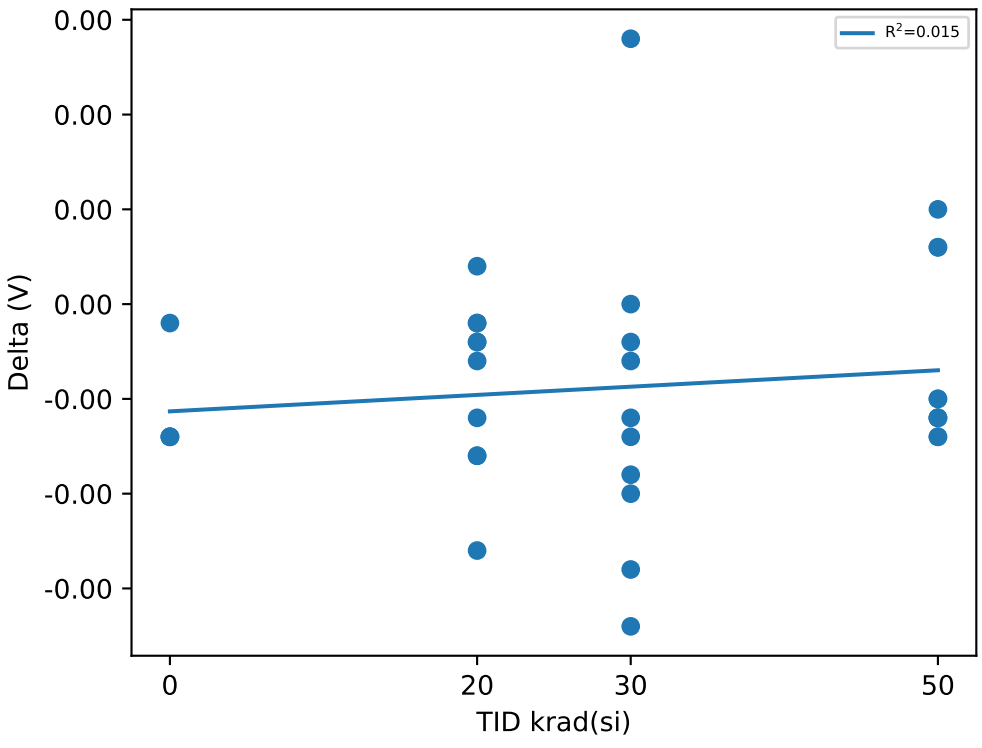
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2224	1.2237	1.2255	0.001314	1.2217	1.2232	1.2248	0.0012685	-0.0007	-0.000525	-0.0001	0.00028723
20	1.218	1.2224	1.2254	0.0023786	1.2182	1.222	1.2252	0.0021538	-0.0013	-0.00044	0.0002	0.00043512
30	1.2206	1.2222	1.2247	0.0013895	1.2196	1.2217	1.2233	0.0011597	-0.0017	-0.00052	0.0014	0.00085997
50	1.2201	1.2223	1.2252	0.0019726	1.2195	1.222	1.2251	0.0021104	-0.0008	-0.00034	0.0005	0.00047656

Device Test: 21.17 VOLTAGE|VREF/VREF/4.5/4.5/0/0/4.5/1MHz//@V_REFCAP

TID vs Result Stats



TID vs Post - Pre Exposure Delta



Test Results (Lower Limit = 1.208, Upper Limit = 1.235 (V))

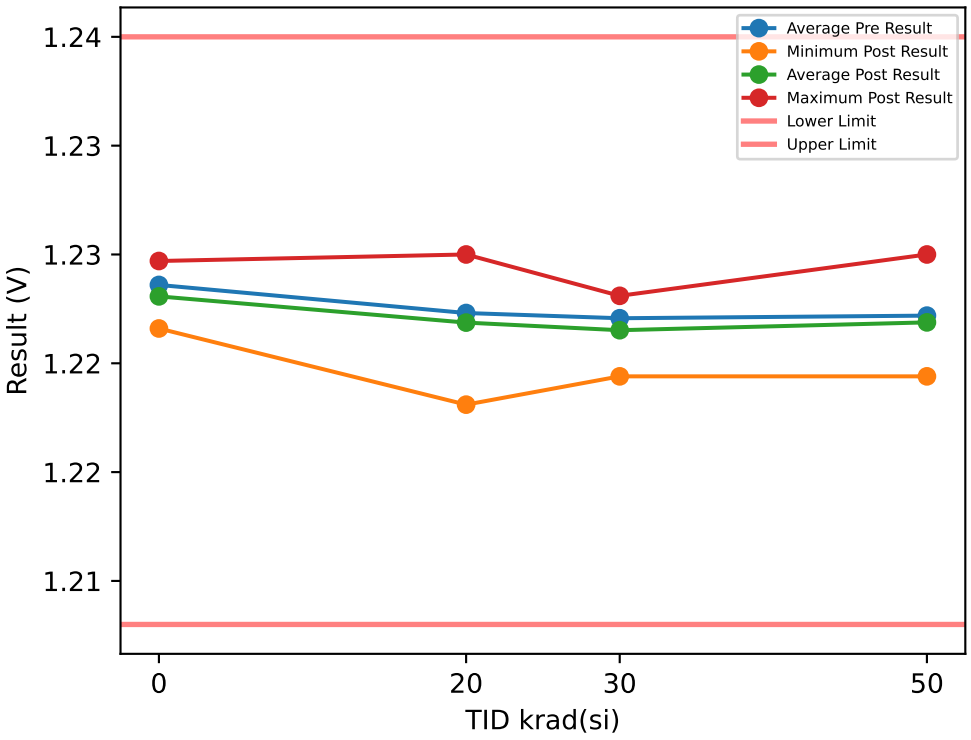
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	1.2218	1.2213	-0.0005
2	20	Unbiased	1.2236	1.2235	-0.0001
3	50	Biased	1.2247	1.224	-0.0007
4	30	Unbiased	1.2222	1.2212	-0.001
5	50	Unbiased	1.2204	1.2198	-0.0006
6	30	Biased	1.2213	1.2207	-0.0006
7	50	Biased	1.2221	1.2214	-0.0007
8	30	Unbiased	1.2212	1.2195	-0.0017
9	20	Unbiased	1.2205	1.2202	-0.0003
10	50	Biased	1.22	1.2195	-0.0005
11	30	Biased	1.2217	1.2214	-0.0003
12	0	Correlation	1.2237	1.223	-0.0007
13	0	Correlation	1.2254	1.2247	-0.0007
14	50	Unbiased	1.2204	1.2198	-0.0006
15	20	Biased	1.2204	1.2202	-0.0002
16	20	Unbiased	1.225	1.2242	-0.0008
17	20	Biased	1.2216	1.221	-0.0006
18	20	Unbiased	1.2244	1.2231	-0.0013
19	20	Biased	1.2215	1.2214	-0.0001
20	50	Unbiased	1.2252	1.2246	-0.0006
21	0	Correlation	1.2224	1.2217	-0.0007
22	50	Unbiased	1.2245	1.225	0.0005
23	0	Correlation	1.2232	1.2231	-0.0001
24	20	Biased	1.2233	1.2225	-0.0008
26	50	Biased	1.2205	1.2208	0.0003
27	30	Unbiased	1.2213	1.2213	0
28	30	Biased	1.2246	1.2232	-0.0014
29	30	Unbiased	1.2239	1.223	-0.0009
30	20	Biased	1.2179	1.2181	0.0002
31	30	Unbiased	1.221	1.2208	-0.0002
33	30	Biased	1.2235	1.2228	-0.0007
34	50	Unbiased	1.2227	1.223	0.0003
35	20	Unbiased	1.2253	1.2251	-0.0002
41	30	Biased	1.2206	1.222	0.0014

Test Statistics (V)

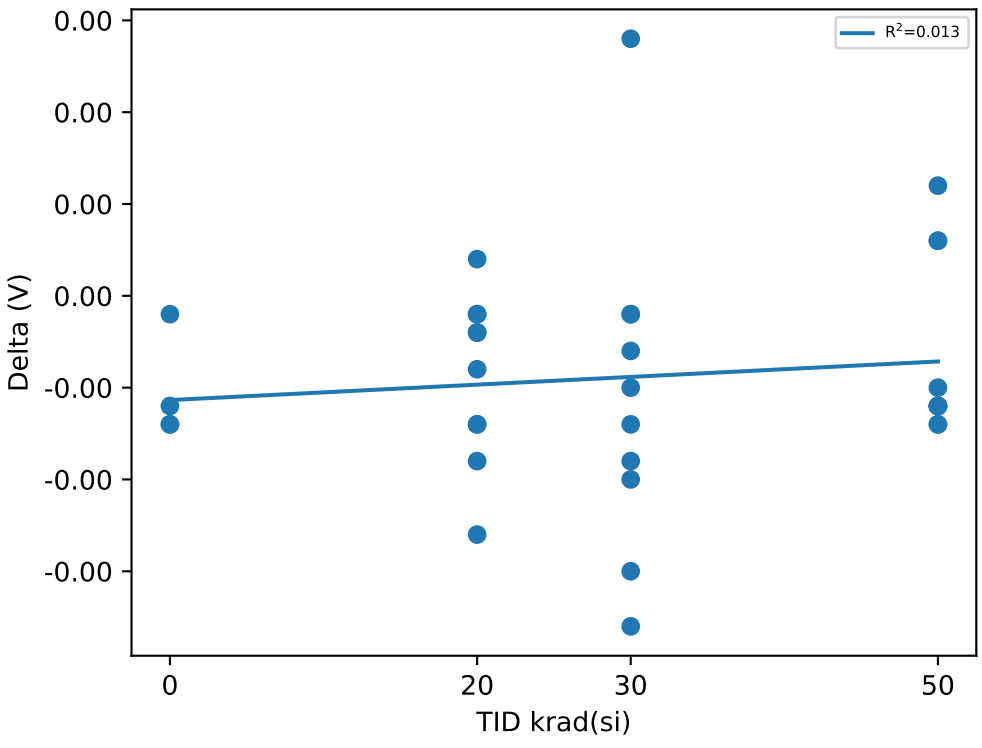
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2224	1.2237	1.2254	0.0012685	1.2217	1.2231	1.2247	0.0012285	-0.0007	-0.00055	-0.0001	0.0003
20	1.2179	1.2224	1.2253	0.0023736	1.2181	1.2219	1.2251	0.0021386	-0.0013	-0.00042	0.0002	0.00044672
30	1.2206	1.2221	1.2246	0.0013809	1.2195	1.2216	1.2232	0.0011676	-0.0017	-0.00054	0.0014	0.00086178
50	1.22	1.2222	1.2252	0.0019766	1.2195	1.2219	1.225	0.0020794	-0.0007	-0.00031	0.0005	0.00047481

Device Test: 21.19 VOLTAGE|VREF/VREF/5/5/0/0/5/1MHz//@V_REFCAP

TID vs Result Stats



TID vs Post - Pre Exposure Delta



Test Results (Lower Limit = 1.208, Upper Limit = 1.235 (V))

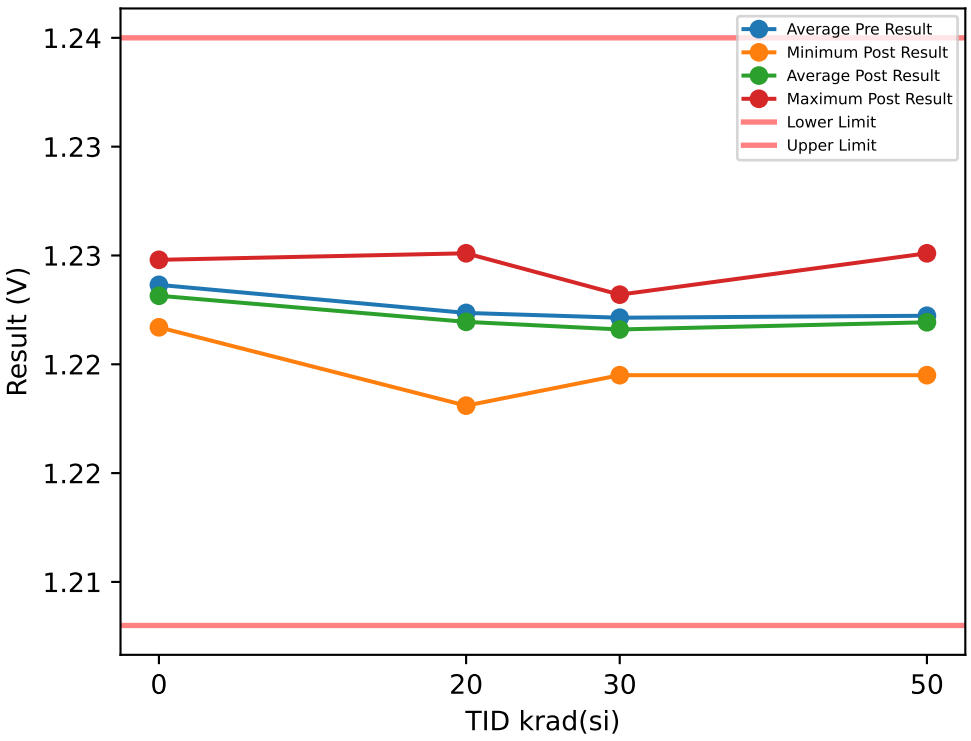
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	1.2218	1.2212	-0.0006
2	20	Unbiased	1.2235	1.2234	-0.0001
3	50	Biased	1.2247	1.224	-0.0007
4	30	Unbiased	1.2221	1.2211	-0.001
5	50	Unbiased	1.2204	1.2198	-0.0006
6	30	Biased	1.2212	1.2207	-0.0005
7	50	Biased	1.222	1.2213	-0.0007
8	30	Unbiased	1.2212	1.2194	-0.0018
9	20	Unbiased	1.2205	1.2201	-0.0004
10	50	Biased	1.22	1.2194	-0.0006
11	30	Biased	1.2216	1.2213	-0.0003
12	0	Correlation	1.2236	1.223	-0.0006
13	0	Correlation	1.2254	1.2247	-0.0007
14	50	Unbiased	1.2203	1.2197	-0.0006
15	20	Biased	1.2203	1.2201	-0.0002
16	20	Unbiased	1.225	1.2241	-0.0009
17	20	Biased	1.2216	1.2209	-0.0007
18	20	Unbiased	1.2244	1.2231	-0.0013
19	20	Biased	1.2215	1.2214	-0.0001
20	50	Unbiased	1.2251	1.2246	-0.0005
21	0	Correlation	1.2223	1.2216	-0.0007
22	50	Unbiased	1.2244	1.225	0.0006
23	0	Correlation	1.2231	1.223	-0.0001
24	20	Biased	1.2232	1.2225	-0.0007
26	50	Biased	1.2205	1.2208	0.0003
27	30	Unbiased	1.2213	1.2212	-0.0001
28	30	Biased	1.2246	1.2231	-0.0015
29	30	Unbiased	1.2238	1.2229	-0.0009
30	20	Biased	1.2179	1.2181	0.0002
31	30	Unbiased	1.2209	1.2208	-0.0001
33	30	Biased	1.2235	1.2228	-0.0007
34	50	Unbiased	1.2227	1.223	0.0003
35	20	Unbiased	1.2252	1.225	-0.0002
41	30	Biased	1.2205	1.2219	0.0014

Test Statistics (V)

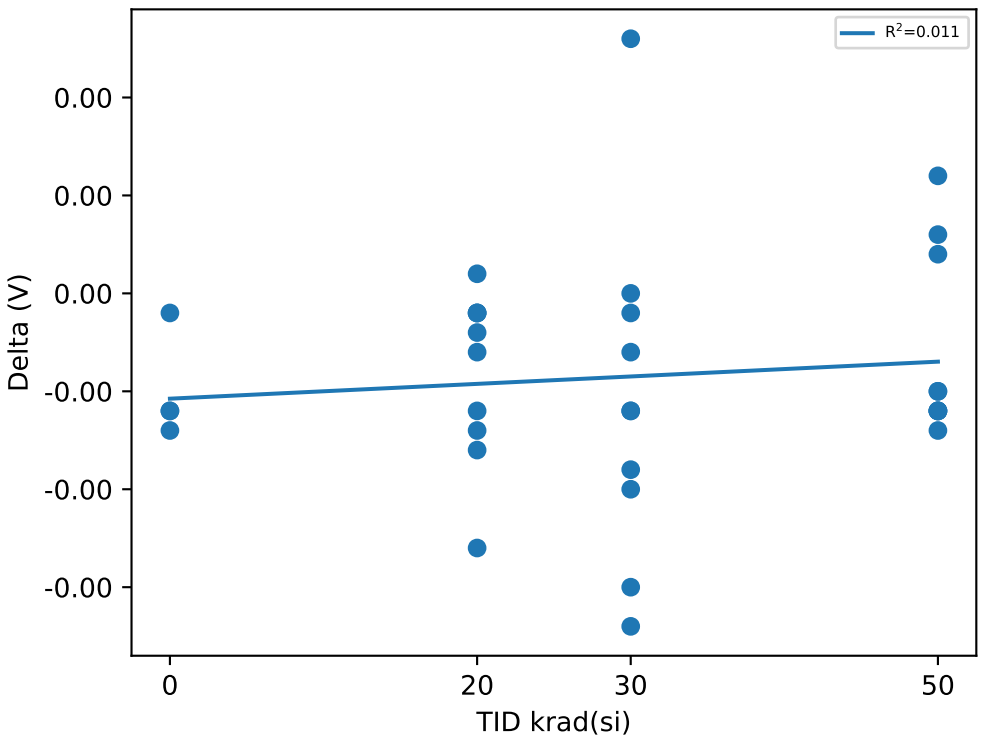
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2223	1.2236	1.2254	0.001314	1.2216	1.2231	1.2247	0.0012685	-0.0007	-0.000525	-0.0001	0.00028723
20	1.2179	1.2223	1.2252	0.0023591	1.2181	1.2219	1.225	0.0021255	-0.0013	-0.00044	0.0002	0.00045265
30	1.2205	1.2221	1.2246	0.0013985	1.2194	1.2215	1.2231	0.0011641	-0.0018	-0.00055	0.0014	0.00088726
50	1.22	1.2222	1.2251	0.0019587	1.2194	1.2219	1.225	0.0021102	-0.0007	-0.00031	0.0006	0.00049989

Device Test: 21.21 VOLTAGE|VREF/VREF/12/12/0/0/5/1MHz//@V_REFCAP

TID vs Result Stats



TID vs Post - Pre Exposure Delta



Test Results (Lower Limit = 1.208, Upper Limit = 1.235 (V))

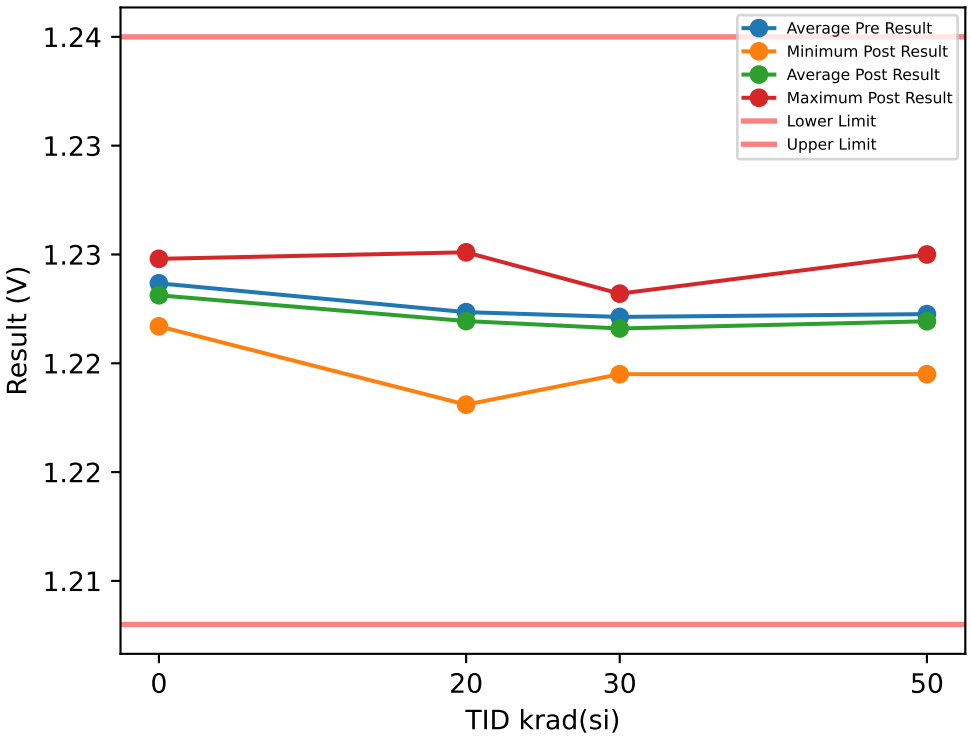
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	1.2218	1.2212	-0.0006
2	20	Unbiased	1.2236	1.2235	-0.0001
3	50	Biased	1.2247	1.224	-0.0007
4	30	Unbiased	1.2222	1.2212	-0.001
5	50	Unbiased	1.2204	1.2198	-0.0006
6	30	Biased	1.2213	1.2207	-0.0006
7	50	Biased	1.222	1.2214	-0.0006
8	30	Unbiased	1.2212	1.2195	-0.0017
9	20	Unbiased	1.2205	1.2202	-0.0003
10	50	Biased	1.22	1.2195	-0.0005
11	30	Biased	1.2217	1.2214	-0.0003
12	0	Correlation	1.2237	1.223	-0.0007
13	0	Correlation	1.2254	1.2248	-0.0006
14	50	Unbiased	1.2204	1.2198	-0.0006
15	20	Biased	1.2203	1.2202	-0.0001
16	20	Unbiased	1.225	1.2242	-0.0008
17	20	Biased	1.2216	1.221	-0.0006
18	20	Unbiased	1.2245	1.2232	-0.0013
19	20	Biased	1.2215	1.2214	-0.0001
20	50	Unbiased	1.2251	1.2246	-0.0005
21	0	Correlation	1.2223	1.2217	-0.0006
22	50	Unbiased	1.2245	1.2251	0.0006
23	0	Correlation	1.2232	1.2231	-0.0001
24	20	Biased	1.2233	1.2226	-0.0007
26	50	Biased	1.2206	1.2209	0.0003
27	30	Unbiased	1.2213	1.2213	0
28	30	Biased	1.2247	1.2232	-0.0015
29	30	Unbiased	1.2239	1.223	-0.0009
30	20	Biased	1.218	1.2181	0.0001
31	30	Unbiased	1.221	1.2209	-0.0001
33	30	Biased	1.2235	1.2229	-0.0006
34	50	Unbiased	1.2228	1.223	0.0002
35	20	Unbiased	1.2253	1.2251	-0.0002
41	30	Biased	1.2206	1.2219	0.0013

Test Statistics (V)

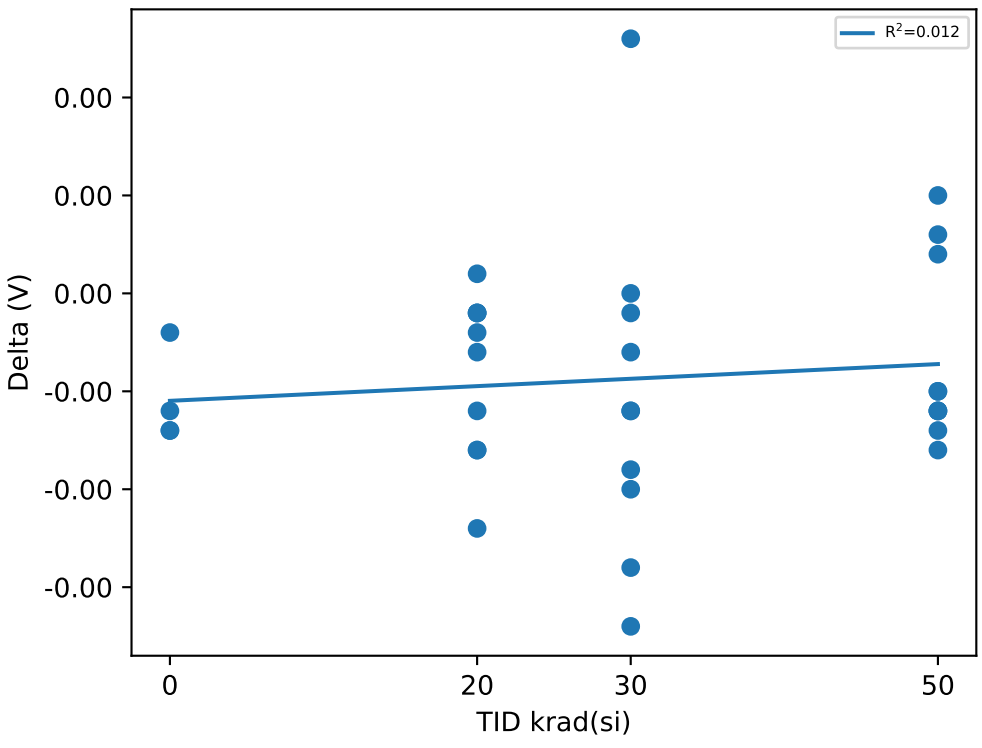
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2223	1.2237	1.2254	0.0013026	1.2217	1.2231	1.2248	0.0012715	-0.0007	-0.0005	-0.0001	0.0002708
20	1.218	1.2224	1.2253	0.0023722	1.2181	1.222	1.2251	0.002148	-0.0013	-0.00041	0.0001	0.00043063
30	1.2206	1.2221	1.2247	0.001401	1.2195	1.2216	1.2232	0.001169	-0.0017	-0.00054	0.0013	0.00085271
50	1.22	1.2222	1.2251	0.0019545	1.2195	1.2219	1.2251	0.0020939	-0.0007	-0.0003	0.0006	0.00047376

Device Test: 21.23 VOLTAGE|VREF/VREF/14/14/0/0/5/1MHz//@V_REFCAP

TID vs Result Stats



TID vs Post - Pre Exposure Delta



Test Results (Lower Limit = 1.208, Upper Limit = 1.235 (V))

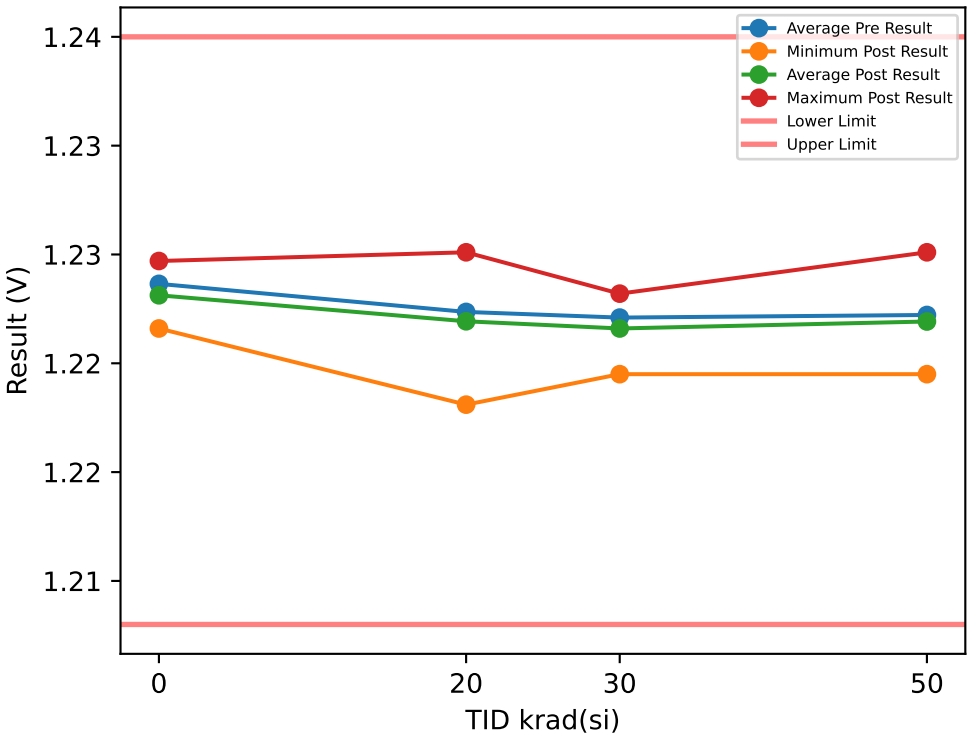
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	1.2219	1.2213	-0.0006
2	20	Unbiased	1.2236	1.2235	-0.0001
3	50	Biased	1.2248	1.224	-0.0008
4	30	Unbiased	1.2222	1.2212	-0.001
5	50	Unbiased	1.2204	1.2198	-0.0006
6	30	Biased	1.2213	1.2207	-0.0006
7	50	Biased	1.2221	1.2214	-0.0007
8	30	Unbiased	1.2212	1.2195	-0.0017
9	20	Unbiased	1.2205	1.2202	-0.0003
10	50	Biased	1.22	1.2195	-0.0005
11	30	Biased	1.2217	1.2214	-0.0003
12	0	Correlation	1.2237	1.223	-0.0007
13	0	Correlation	1.2255	1.2248	-0.0007
14	50	Unbiased	1.2204	1.2198	-0.0006
15	20	Biased	1.2203	1.2202	-0.0001
16	20	Unbiased	1.225	1.2242	-0.0008
17	20	Biased	1.2216	1.221	-0.0006
18	20	Unbiased	1.2244	1.2232	-0.0012
19	20	Biased	1.2215	1.2214	-0.0001
20	50	Unbiased	1.2251	1.2246	-0.0005
21	0	Correlation	1.2223	1.2217	-0.0006
22	50	Unbiased	1.2245	1.225	0.0005
23	0	Correlation	1.2232	1.223	-0.0002
24	20	Biased	1.2233	1.2225	-0.0008
26	50	Biased	1.2206	1.2209	0.0003
27	30	Unbiased	1.2213	1.2213	0
28	30	Biased	1.2246	1.2232	-0.0014
29	30	Unbiased	1.2239	1.223	-0.0009
30	20	Biased	1.218	1.2181	0.0001
31	30	Unbiased	1.221	1.2209	-0.0001
33	30	Biased	1.2235	1.2229	-0.0006
34	50	Unbiased	1.2228	1.223	0.0002
35	20	Unbiased	1.2253	1.2251	-0.0002
41	30	Biased	1.2206	1.2219	0.0013

Test Statistics (V)

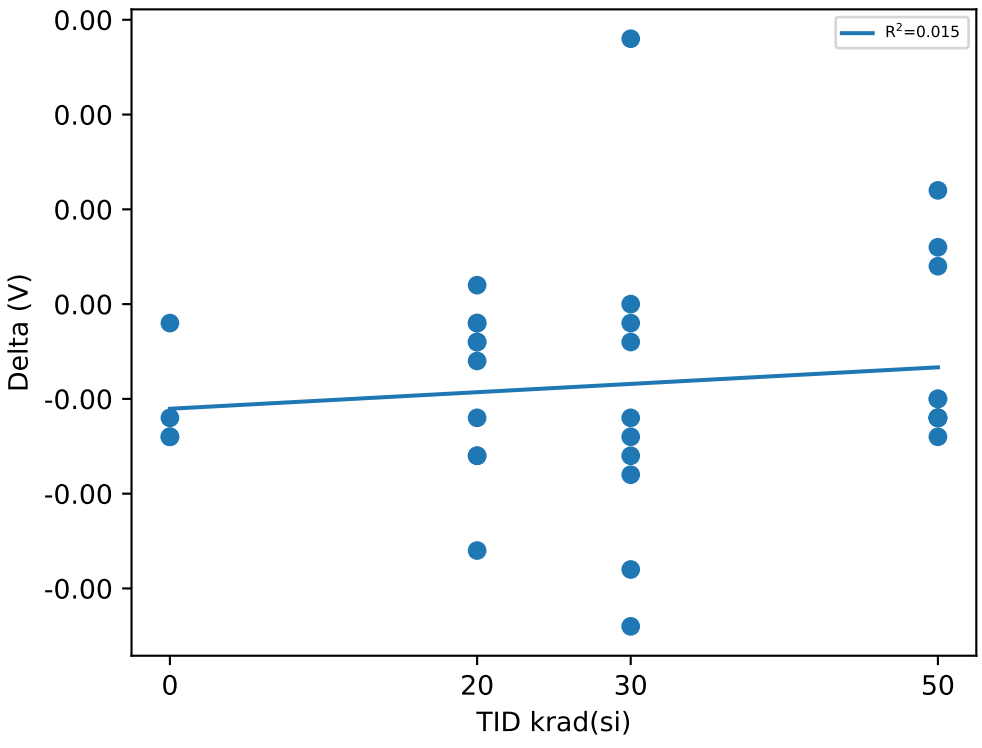
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2223	1.2237	1.2255	0.0013475	1.2217	1.2231	1.2248	0.0012738	-0.0007	-0.00055	-0.0002	0.00023805
20	1.218	1.2224	1.2253	0.0023623	1.2181	1.2219	1.2251	0.0021449	-0.0012	-0.00041	0.0001	0.00041753
30	1.2206	1.2221	1.2246	0.0013809	1.2195	1.2216	1.2232	0.001169	-0.0017	-0.00053	0.0013	0.0008407
50	1.22	1.2223	1.2251	0.0019654	1.2195	1.2219	1.225	0.0020737	-0.0008	-0.00033	0.0005	0.00047152

Device Test: 21.25 VOLTAGE|VREF/VREF/4.5/4.5/0/1000/4.5/100kHz//@V_REFCAP

TID vs Result Stats



TID vs Post - Pre Exposure Delta



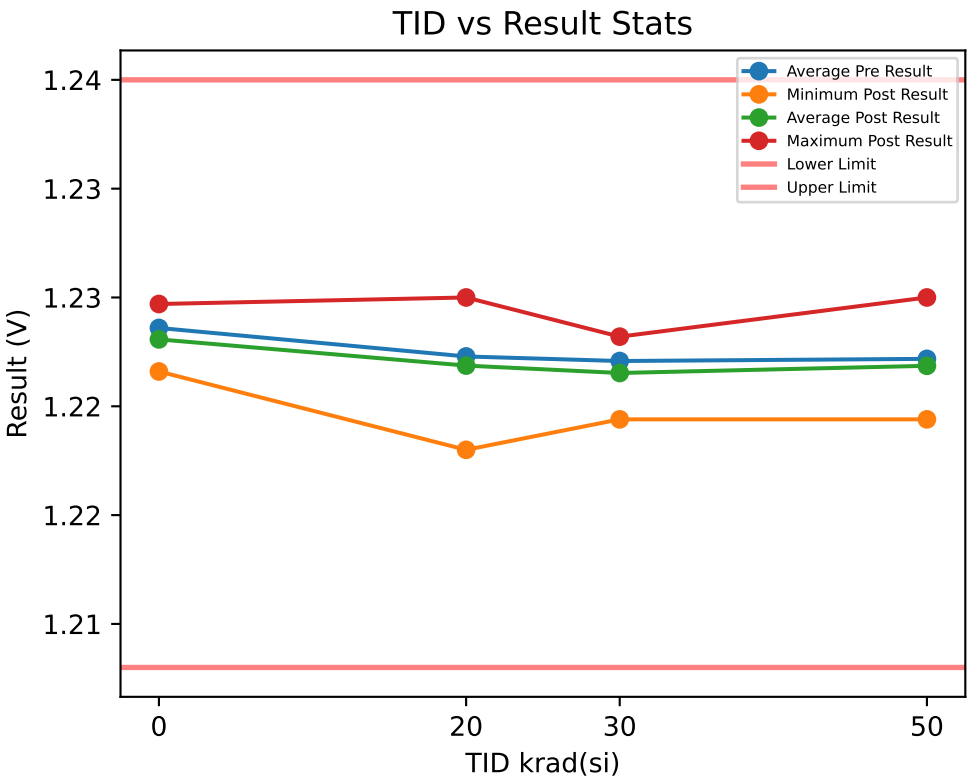
Test Results (Lower Limit = 1.208, Upper Limit = 1.235 (V))

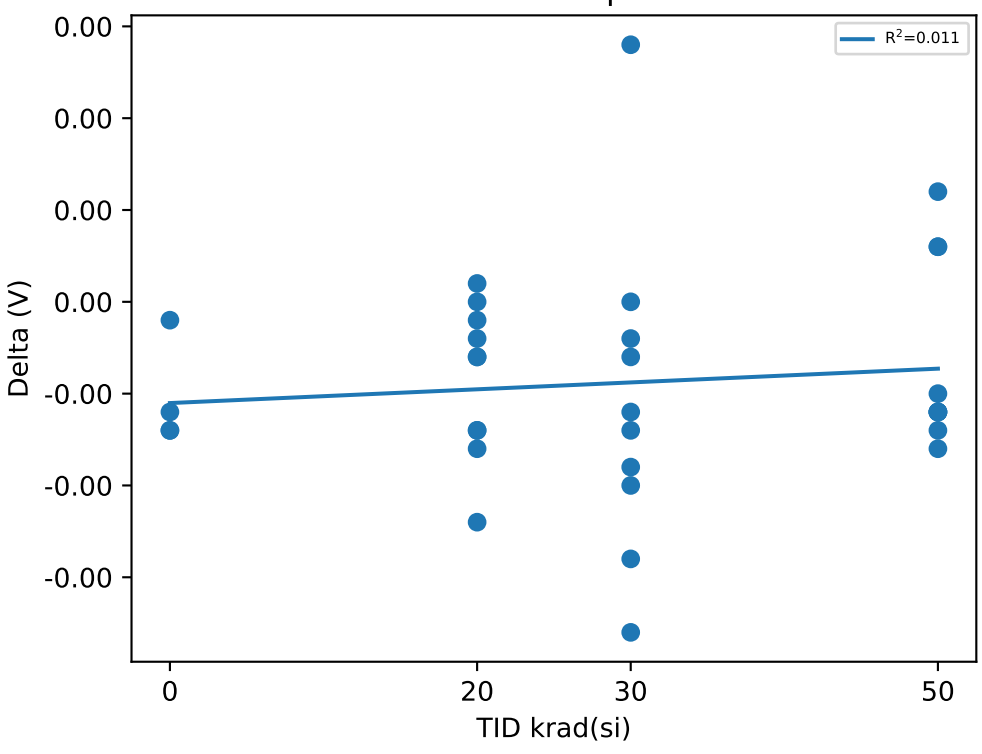
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	1.2218	1.2212	-0.0006
2	20	Unbiased	1.2236	1.2235	-0.0001
3	50	Biased	1.2247	1.224	-0.0007
4	30	Unbiased	1.2221	1.2212	-0.0009
5	50	Unbiased	1.2204	1.2198	-0.0006
6	30	Biased	1.2213	1.2207	-0.0006
7	50	Biased	1.222	1.2214	-0.0006
8	30	Unbiased	1.2212	1.2195	-0.0017
9	20	Unbiased	1.2205	1.2202	-0.0003
10	50	Biased	1.22	1.2195	-0.0005
11	30	Biased	1.2216	1.2214	-0.0002
12	0	Correlation	1.2237	1.2231	-0.0006
13	0	Correlation	1.2254	1.2247	-0.0007
14	50	Unbiased	1.2204	1.2198	-0.0006
15	20	Biased	1.2204	1.2202	-0.0002
16	20	Unbiased	1.225	1.2242	-0.0008
17	20	Biased	1.2216	1.221	-0.0006
18	20	Unbiased	1.2244	1.2231	-0.0013
19	20	Biased	1.2215	1.2214	-0.0001
20	50	Unbiased	1.2251	1.2246	-0.0005
21	0	Correlation	1.2223	1.2216	-0.0007
22	50	Unbiased	1.2245	1.2251	0.0006
23	0	Correlation	1.2232	1.2231	-0.0001
24	20	Biased	1.2233	1.2225	-0.0008
26	50	Biased	1.2206	1.2208	0.0002
27	30	Unbiased	1.2213	1.2213	0
28	30	Biased	1.2246	1.2232	-0.0014
29	30	Unbiased	1.2238	1.223	-0.0008
30	20	Biased	1.218	1.2181	0.0001
31	30	Unbiased	1.221	1.2209	-0.0001
33	30	Biased	1.2235	1.2228	-0.0007
34	50	Unbiased	1.2227	1.223	0.0003
35	20	Unbiased	1.2253	1.2251	-0.0002
41	30	Biased	1.2206	1.222	0.0014

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2223	1.2237	1.2254	0.0013026	1.2216	1.2231	1.2247	0.0012659	-0.0007	-0.000525	-0.0001	0.00028723
20	1.218	1.2224	1.2253	0.0023529	1.2181	1.2219	1.2251	0.0021386	-0.0013	-0.00043	0.0001	0.00043218
30	1.2206	1.2221	1.2246	0.0013703	1.2195	1.2216	1.2232	0.0011605	-0.0017	-0.0005	0.0014	0.00086023
50	1.22	1.2222	1.2251	0.0019515	1.2195	1.2219	1.2251	0.0020996	-0.0007	-0.0003	0.0006	0.00047376

Device Test: 21.27 VOLTAGE|VREF/VREF/5/5/0/1000/5/100kHz//@V_REFCAP





Test Results (Lower Limit = 1.208, Upper Limit = 1.235 (V))

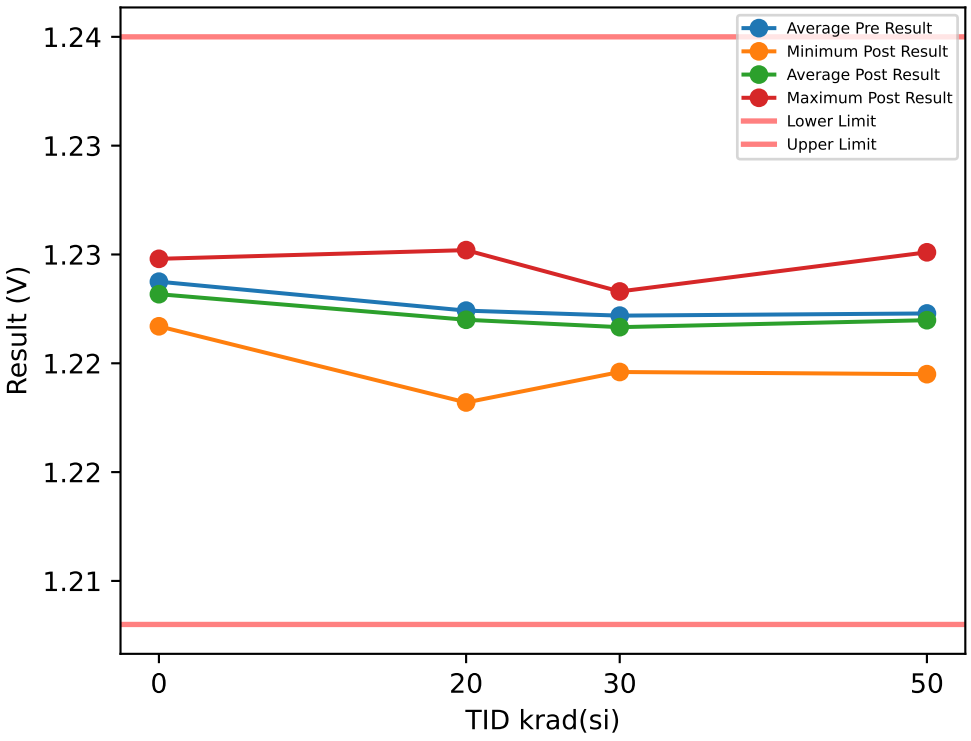
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	1.2218	1.2212	-0.0006
2	20	Unbiased	1.2235	1.2235	0
3	50	Biased	1.2247	1.2239	-0.0008
4	30	Unbiased	1.2221	1.2211	-0.001
5	50	Unbiased	1.2203	1.2197	-0.0006
6	30	Biased	1.2212	1.2206	-0.0006
7	50	Biased	1.222	1.2213	-0.0007
8	30	Unbiased	1.2212	1.2194	-0.0018
9	20	Unbiased	1.2204	1.2201	-0.0003
10	50	Biased	1.22	1.2194	-0.0006
11	30	Biased	1.2216	1.2213	-0.0003
12	0	Correlation	1.2236	1.223	-0.0006
13	0	Correlation	1.2254	1.2247	-0.0007
14	50	Unbiased	1.2203	1.2197	-0.0006
15	20	Biased	1.2203	1.2201	-0.0002
16	20	Unbiased	1.2249	1.2242	-0.0007
17	20	Biased	1.2216	1.2209	-0.0007
18	20	Unbiased	1.2243	1.2231	-0.0012
19	20	Biased	1.2215	1.2214	-0.0001
20	50	Unbiased	1.2251	1.2246	-0.0005
21	0	Correlation	1.2223	1.2216	-0.0007
22	50	Unbiased	1.2244	1.225	0.0006
23	0	Correlation	1.2231	1.223	-0.0001
24	20	Biased	1.2232	1.2224	-0.0008
26	50	Biased	1.2205	1.2208	0.0003
27	30	Unbiased	1.2213	1.2213	0
28	30	Biased	1.2246	1.2232	-0.0014
29	30	Unbiased	1.2238	1.2229	-0.0009
30	20	Biased	1.2179	1.218	0.0001
31	30	Unbiased	1.221	1.2208	-0.0002
33	30	Biased	1.2235	1.2228	-0.0007
34	50	Unbiased	1.2227	1.223	0.0003
35	20	Unbiased	1.2253	1.225	-0.0003
41	30	Biased	1.2205	1.2219	0.0014

Test Statistics (V)

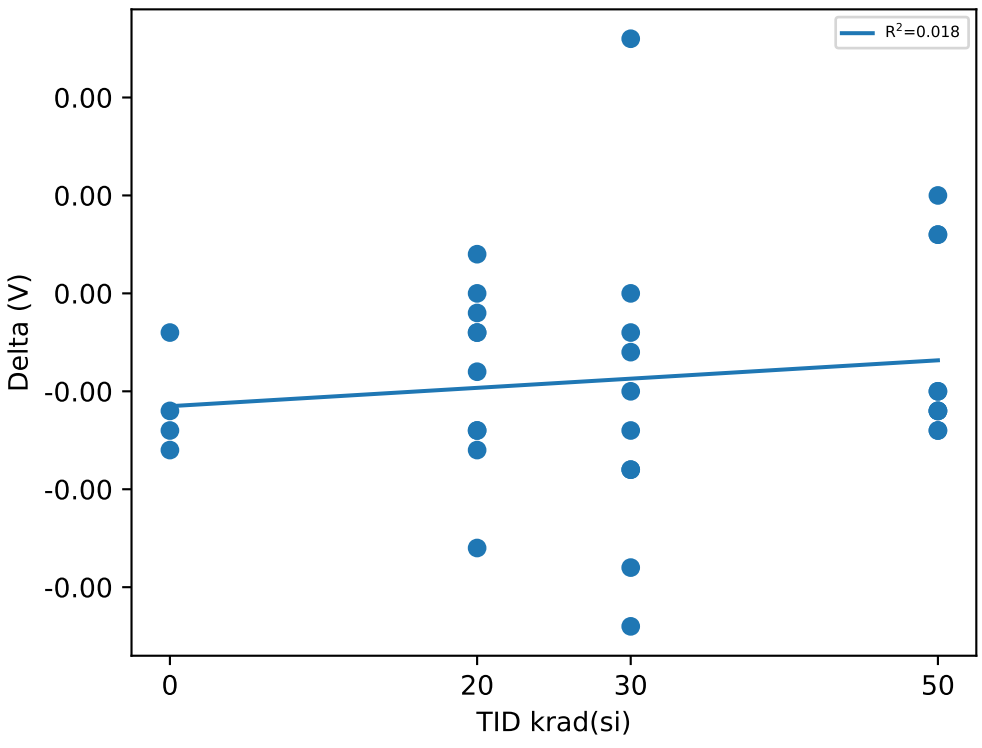
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2223	1.2236	1.2254	0.001314	1.2216	1.2231	1.2247	0.0012685	-0.0007	-0.000525	-0.0001	0.00028723
20	1.2179	1.2223	1.2253	0.0023596	1.218	1.2219	1.225	0.0021623	-0.0012	-0.00042	0.0001	0.00041312
30	1.2205	1.2221	1.2246	0.0013895	1.2194	1.2215	1.2232	0.0011851	-0.0018	-0.00055	0.0014	0.00087718
50	1.22	1.2222	1.2251	0.0019691	1.2194	1.2219	1.225	0.0021104	-0.0008	-0.00032	0.0006	0.00050947

Device Test: 21.29 VOLTAGE|VREF/VREF/12/12/0/1000/5/100kHz//@V_REFCAP

TID vs Result Stats



TID vs Post - Pre Exposure Delta



Test Results (Lower Limit = 1.208, Upper Limit = 1.235 (V))

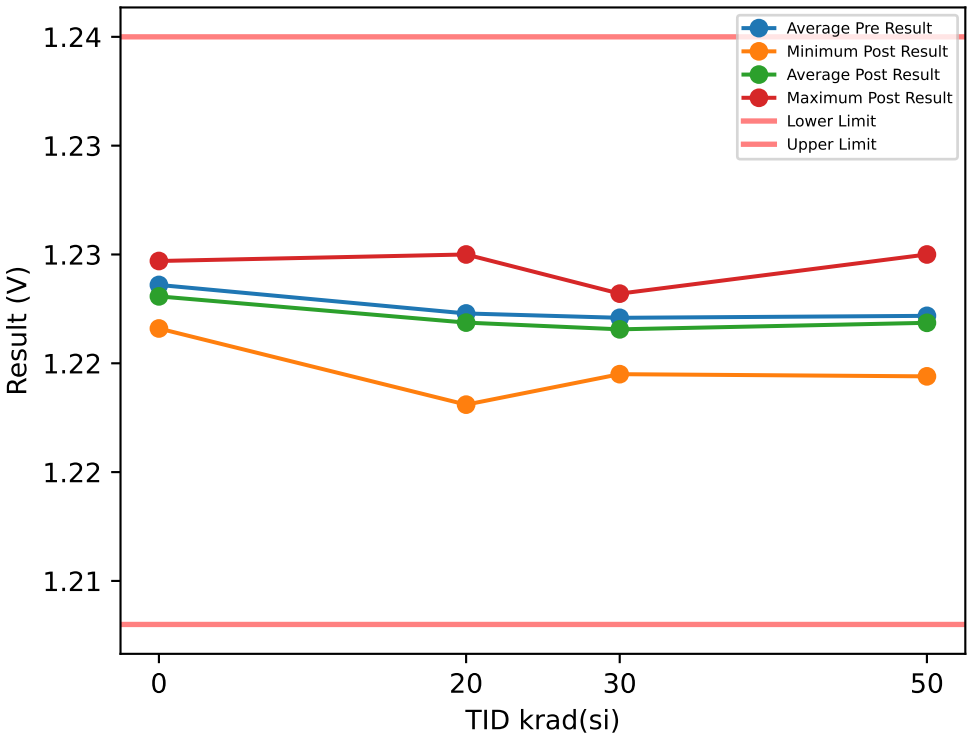
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	1.2219	1.2213	-0.0006
2	20	Unbiased	1.2236	1.2236	0
3	50	Biased	1.2248	1.2241	-0.0007
4	30	Unbiased	1.2222	1.2213	-0.0009
5	50	Unbiased	1.2204	1.2199	-0.0005
6	30	Biased	1.2213	1.2208	-0.0005
7	50	Biased	1.2221	1.2214	-0.0007
8	30	Unbiased	1.2213	1.2196	-0.0017
9	20	Unbiased	1.2206	1.2202	-0.0004
10	50	Biased	1.2201	1.2195	-0.0006
11	30	Biased	1.2217	1.2214	-0.0003
12	0	Correlation	1.2237	1.2231	-0.0006
13	0	Correlation	1.2255	1.2248	-0.0007
14	50	Unbiased	1.2204	1.2198	-0.0006
15	20	Biased	1.2204	1.2202	-0.0002
16	20	Unbiased	1.225	1.2243	-0.0007
17	20	Biased	1.2217	1.221	-0.0007
18	20	Unbiased	1.2245	1.2232	-0.0013
19	20	Biased	1.2216	1.2215	-0.0001
20	50	Unbiased	1.2252	1.2247	-0.0005
21	0	Correlation	1.2225	1.2217	-0.0008
22	50	Unbiased	1.2246	1.2251	0.0005
23	0	Correlation	1.2233	1.2231	-0.0002
24	20	Biased	1.2234	1.2226	-0.0008
26	50	Biased	1.2206	1.2209	0.0003
27	30	Unbiased	1.2214	1.2214	0
28	30	Biased	1.2247	1.2233	-0.0014
29	30	Unbiased	1.2239	1.223	-0.0009
30	20	Biased	1.218	1.2182	0.0002
31	30	Unbiased	1.2211	1.2209	-0.0002
33	30	Biased	1.2236	1.2229	-0.0007
34	50	Unbiased	1.2228	1.2231	0.0003
35	20	Unbiased	1.2254	1.2252	-0.0002
41	30	Biased	1.2207	1.222	0.0013

Test Statistics (V)

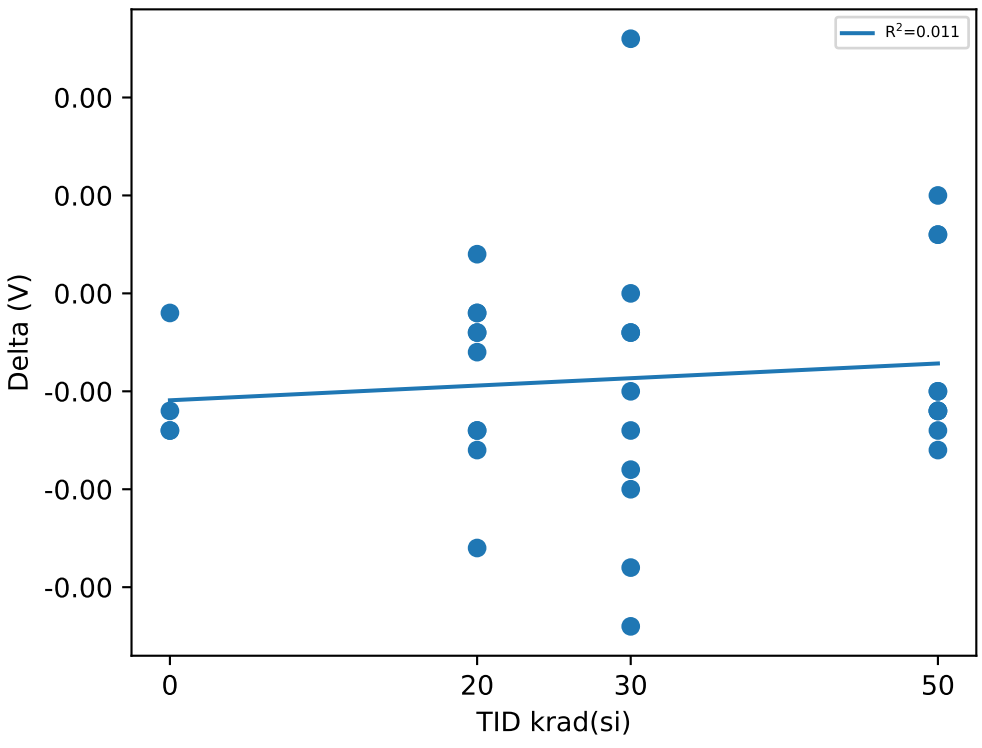
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2225	1.2237	1.2255	0.0012689	1.2217	1.2232	1.2248	0.0012685	-0.0008	-0.000575	-0.0002	0.000263
20	1.218	1.2224	1.2254	0.0023649	1.2182	1.222	1.2252	0.0021618	-0.0013	-0.00042	0.0002	0.00045166
30	1.2207	1.2222	1.2247	0.0013772	1.2196	1.2217	1.2233	0.001153	-0.0017	-0.00053	0.0013	0.0008314
50	1.2201	1.2223	1.2252	0.0019818	1.2195	1.222	1.2251	0.0021102	-0.0007	-0.00031	0.0005	0.00047481

Device Test: 21.3 VOLTAGE|VREF/VREF/5/5/0/0/5/100kHz//@V_REFCAP

TID vs Result Stats



TID vs Post - Pre Exposure Delta



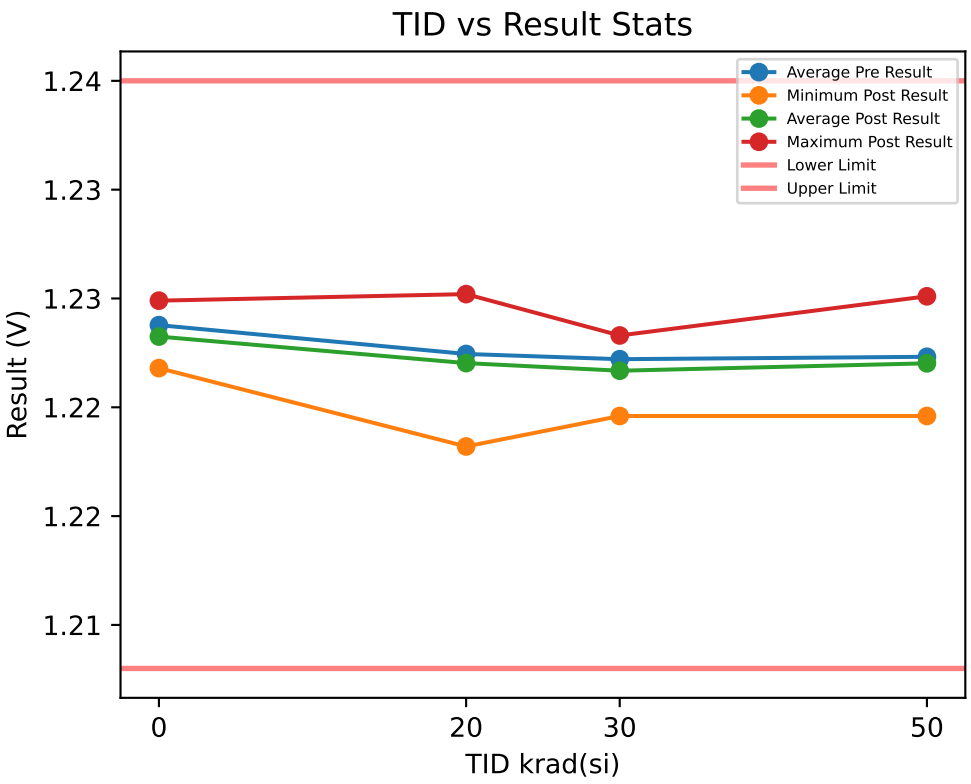
Test Results (Lower Limit = 1.208, Upper Limit = 1.235 (V))

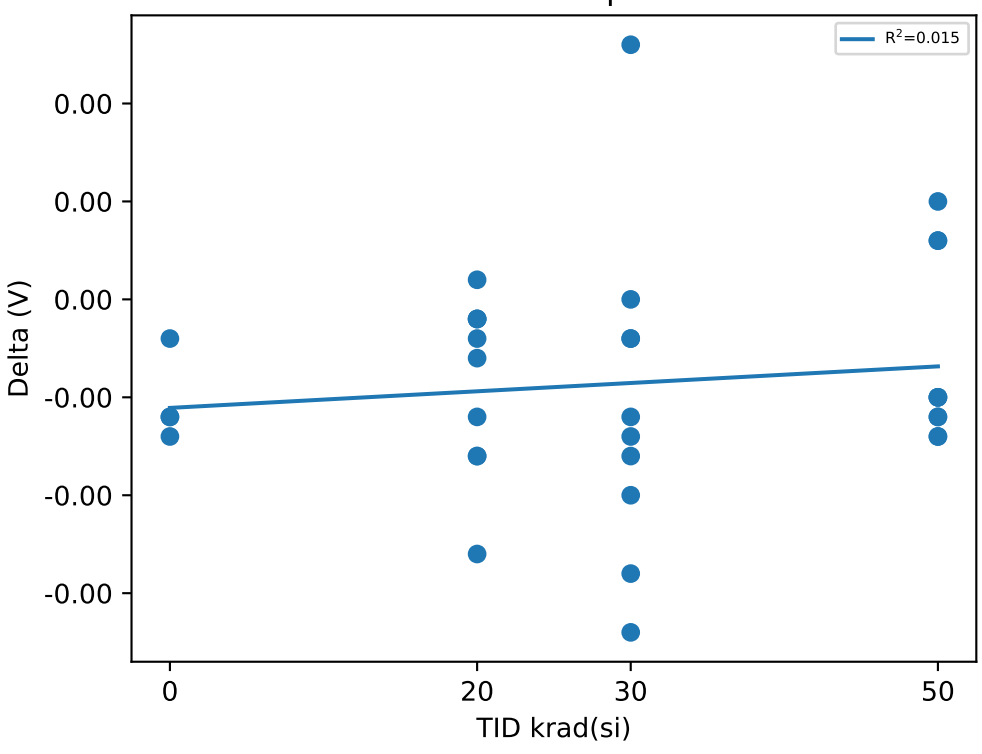
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	1.2218	1.2212	-0.0006
2	20	Unbiased	1.2235	1.2234	-0.0001
3	50	Biased	1.2247	1.2239	-0.0008
4	30	Unbiased	1.2221	1.2211	-0.001
5	50	Unbiased	1.2203	1.2197	-0.0006
6	30	Biased	1.2212	1.2207	-0.0005
7	50	Biased	1.222	1.2213	-0.0007
8	30	Unbiased	1.2212	1.2195	-0.0017
9	20	Unbiased	1.2204	1.2201	-0.0003
10	50	Biased	1.2199	1.2194	-0.0005
11	30	Biased	1.2216	1.2214	-0.0002
12	0	Correlation	1.2236	1.223	-0.0006
13	0	Correlation	1.2254	1.2247	-0.0007
14	50	Unbiased	1.2203	1.2197	-0.0006
15	20	Biased	1.2203	1.2201	-0.0002
16	20	Unbiased	1.2249	1.2241	-0.0008
17	20	Biased	1.2216	1.2209	-0.0007
18	20	Unbiased	1.2244	1.2231	-0.0013
19	20	Biased	1.2215	1.2214	-0.0001
20	50	Unbiased	1.2251	1.2246	-0.0005
21	0	Correlation	1.2223	1.2216	-0.0007
22	50	Unbiased	1.2245	1.225	0.0005
23	0	Correlation	1.2231	1.223	-0.0001
24	20	Biased	1.2232	1.2225	-0.0007
26	50	Biased	1.2205	1.2208	0.0003
27	30	Unbiased	1.2213	1.2213	0
28	30	Biased	1.2246	1.2232	-0.0014
29	30	Unbiased	1.2238	1.2229	-0.0009
30	20	Biased	1.2179	1.2181	0.0002
31	30	Unbiased	1.221	1.2208	-0.0002
33	30	Biased	1.2235	1.2228	-0.0007
34	50	Unbiased	1.2227	1.223	0.0003
35	20	Unbiased	1.2252	1.225	-0.0002
41	30	Biased	1.2206	1.2219	0.0013

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2223	1.2236	1.2254	0.001314	1.2216	1.2231	1.2247	0.0012685	-0.0007	-0.000525	-0.0001	0.00028723
20	1.2179	1.2223	1.2252	0.0023553	1.2181	1.2219	1.225	0.0021255	-0.0013	-0.00042	0.0002	0.00044422
30	1.2206	1.2221	1.2246	0.0013772	1.2195	1.2216	1.2232	0.0011549	-0.0017	-0.00053	0.0013	0.0008407
50	1.2199	1.2222	1.2251	0.0019943	1.2194	1.2219	1.225	0.0021104	-0.0008	-0.00032	0.0005	0.00048488

Device Test: 21.31 VOLTAGE|VREF/VREF/14/14/0/1000/5/100kHz//@V_REFCAP





Test Results (Lower Limit = 1.208, Upper Limit = 1.235 (V))

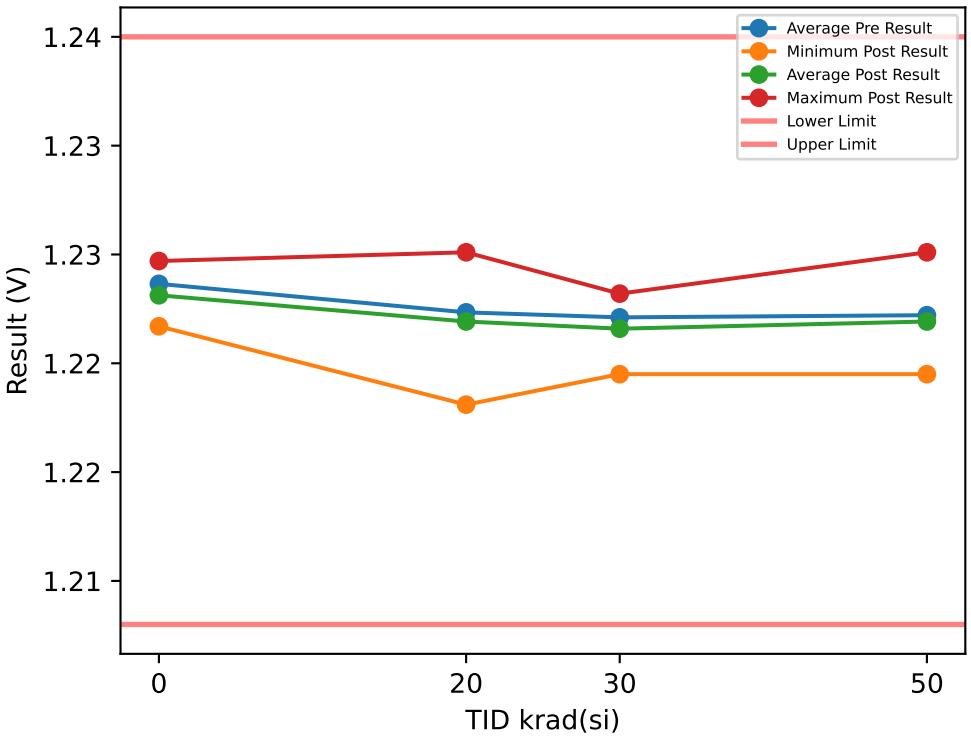
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	1.2219	1.2213	-0.0006
2	20	Unbiased	1.2237	1.2236	-0.0001
3	50	Biased	1.2248	1.2241	-0.0007
4	30	Unbiased	1.2223	1.2213	-0.001
5	50	Unbiased	1.2205	1.2199	-0.0006
6	30	Biased	1.2214	1.2208	-0.0006
7	50	Biased	1.2222	1.2215	-0.0007
8	30	Unbiased	1.2213	1.2196	-0.0017
9	20	Unbiased	1.2206	1.2203	-0.0003
10	50	Biased	1.2201	1.2196	-0.0005
11	30	Biased	1.2217	1.2215	-0.0002
12	0	Correlation	1.2238	1.2232	-0.0006
13	0	Correlation	1.2255	1.2249	-0.0006
14	50	Unbiased	1.2204	1.2199	-0.0005
15	20	Biased	1.2204	1.2203	-0.0001
16	20	Unbiased	1.2251	1.2243	-0.0008
17	20	Biased	1.2217	1.2211	-0.0006
18	20	Unbiased	1.2245	1.2232	-0.0013
19	20	Biased	1.2216	1.2215	-0.0001
20	50	Unbiased	1.2252	1.2247	-0.0005
21	0	Correlation	1.2225	1.2218	-0.0007
22	50	Unbiased	1.2246	1.2251	0.0005
23	0	Correlation	1.2233	1.2231	-0.0002
24	20	Biased	1.2234	1.2226	-0.0008
26	50	Biased	1.2207	1.221	0.0003
27	30	Unbiased	1.2214	1.2214	0
28	30	Biased	1.2247	1.2233	-0.0014
29	30	Unbiased	1.2239	1.2231	-0.0008
30	20	Biased	1.2181	1.2182	0.0001
31	30	Unbiased	1.2211	1.2209	-0.0002
33	30	Biased	1.2236	1.2229	-0.0007
34	50	Unbiased	1.2228	1.2231	0.0003
35	20	Unbiased	1.2254	1.2252	-0.0002
41	30	Biased	1.2207	1.222	0.0013

Test Statistics (V)

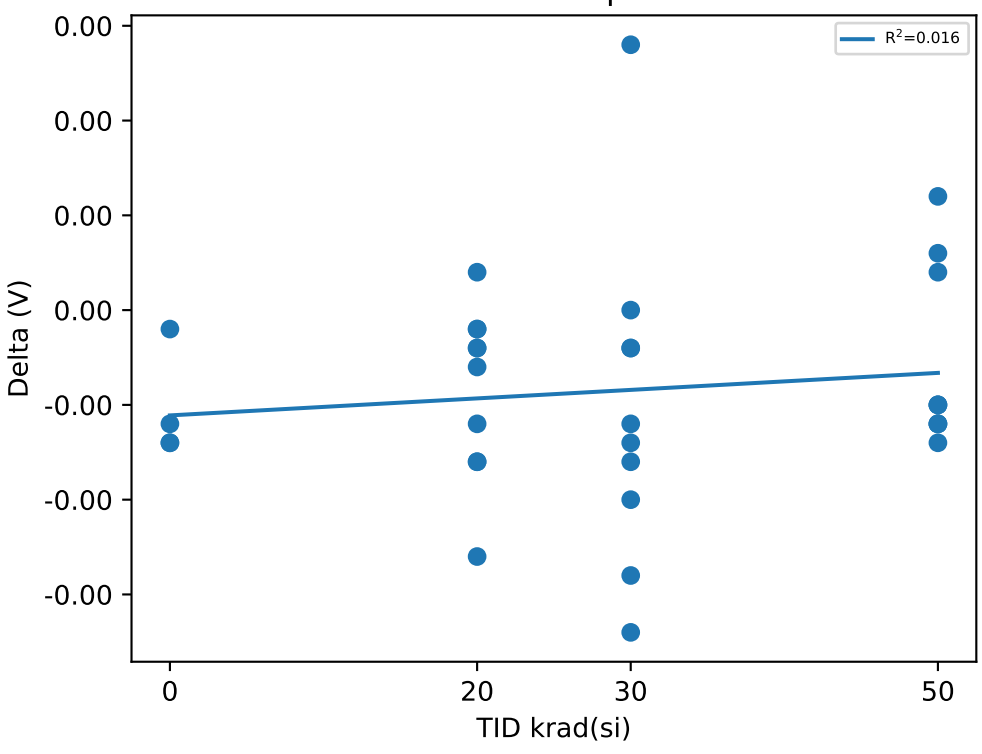
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2225	1.2238	1.2255	0.0012685	1.2218	1.2233	1.2249	0.0012715	-0.0007	-0.000525	-0.0002	0.00022174
20	1.2181	1.2224	1.2254	0.0023623	1.2182	1.222	1.2252	0.0021386	-0.0013	-0.00042	0.0001	0.00043919
30	1.2207	1.2222	1.2247	0.0013707	1.2196	1.2217	1.2233	0.0011641	-0.0017	-0.00053	0.0013	0.00083673
50	1.2201	1.2223	1.2252	0.0019612	1.2196	1.222	1.2251	0.0020773	-0.0007	-0.0003	0.0005	0.00046904

Device Test: 21.33 VOLTAGE|VREF/VREF/4.5/4.5/0/1000/4.5/500kHz//@V_REFCAP

TID vs Result Stats



TID vs Post - Pre Exposure Delta



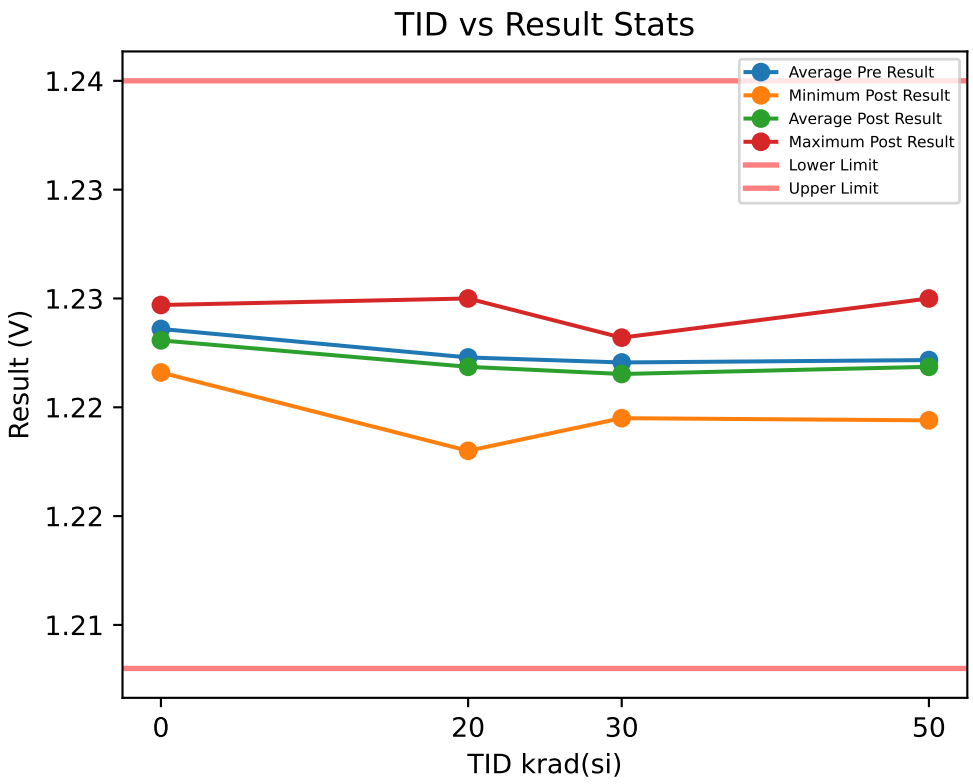
Test Results (Lower Limit = 1.208, Upper Limit = 1.235 (V))

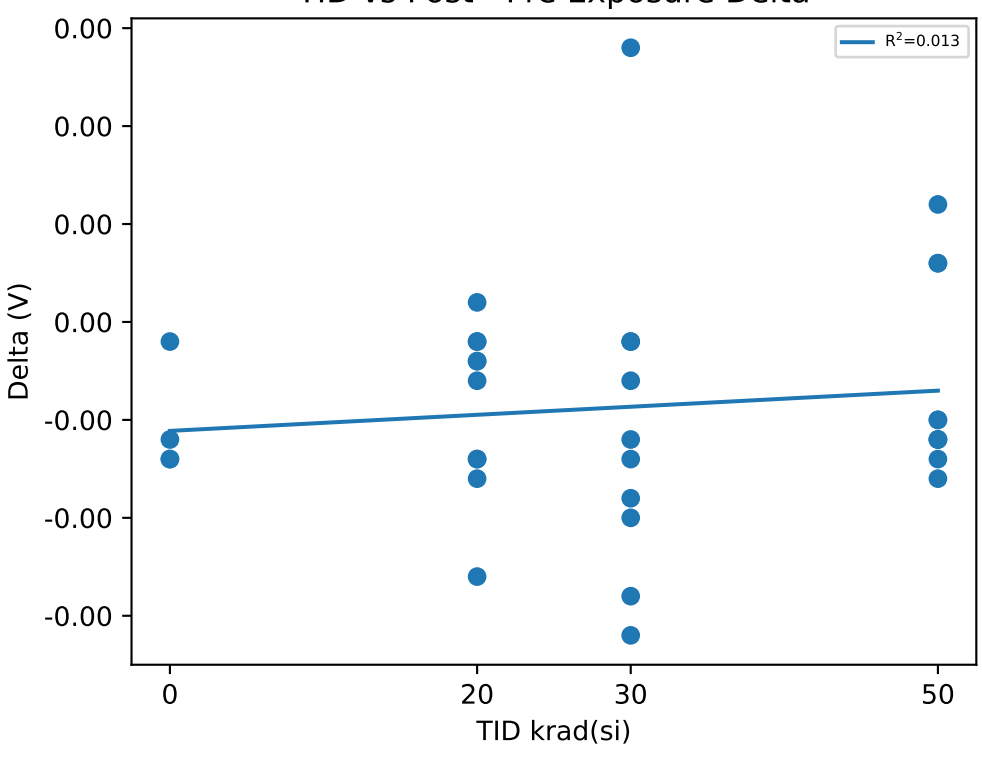
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	1.2218	1.2212	-0.0006
2	20	Unbiased	1.2236	1.2235	-0.0001
3	50	Biased	1.2247	1.224	-0.0007
4	30	Unbiased	1.2222	1.2212	-0.001
5	50	Unbiased	1.2204	1.2198	-0.0006
6	30	Biased	1.2213	1.2207	-0.0006
7	50	Biased	1.222	1.2214	-0.0006
8	30	Unbiased	1.2212	1.2195	-0.0017
9	20	Unbiased	1.2205	1.2202	-0.0003
10	50	Biased	1.22	1.2195	-0.0005
11	30	Biased	1.2216	1.2214	-0.0002
12	0	Correlation	1.2236	1.223	-0.0006
13	0	Correlation	1.2254	1.2247	-0.0007
14	50	Unbiased	1.2203	1.2198	-0.0005
15	20	Biased	1.2203	1.2201	-0.0002
16	20	Unbiased	1.225	1.2242	-0.0008
17	20	Biased	1.2216	1.221	-0.0006
18	20	Unbiased	1.2244	1.2231	-0.0013
19	20	Biased	1.2215	1.2214	-0.0001
20	50	Unbiased	1.2251	1.2246	-0.0005
21	0	Correlation	1.2224	1.2217	-0.0007
22	50	Unbiased	1.2245	1.2251	0.0006
23	0	Correlation	1.2232	1.2231	-0.0001
24	20	Biased	1.2233	1.2225	-0.0008
26	50	Biased	1.2206	1.2208	0.0002
27	30	Unbiased	1.2213	1.2213	0
28	30	Biased	1.2246	1.2232	-0.0014
29	30	Unbiased	1.2238	1.223	-0.0008
30	20	Biased	1.2179	1.2181	0.0002
31	30	Unbiased	1.221	1.2208	-0.0002
33	30	Biased	1.2235	1.2228	-0.0007
34	50	Unbiased	1.2227	1.223	0.0003
35	20	Unbiased	1.2253	1.2251	-0.0002
41	30	Biased	1.2206	1.222	0.0014

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2224	1.2237	1.2254	0.0012689	1.2217	1.2231	1.2247	0.0012285	-0.0007	-0.000525	-0.0001	0.00028723
20	1.2179	1.2223	1.2253	0.0023829	1.2181	1.2219	1.2251	0.0021478	-0.0013	-0.00042	0.0002	0.00044672
30	1.2206	1.2221	1.2246	0.0013707	1.2195	1.2216	1.2232	0.0011676	-0.0017	-0.00052	0.0014	0.00086127
50	1.22	1.2222	1.2251	0.0019621	1.2195	1.2219	1.2251	0.0020996	-0.0007	-0.00029	0.0006	0.00046774

Device Test: 21.35 VOLTAGE|VREF/VREF/5/5/0/1000/5/500kHz//@V_REFCAP





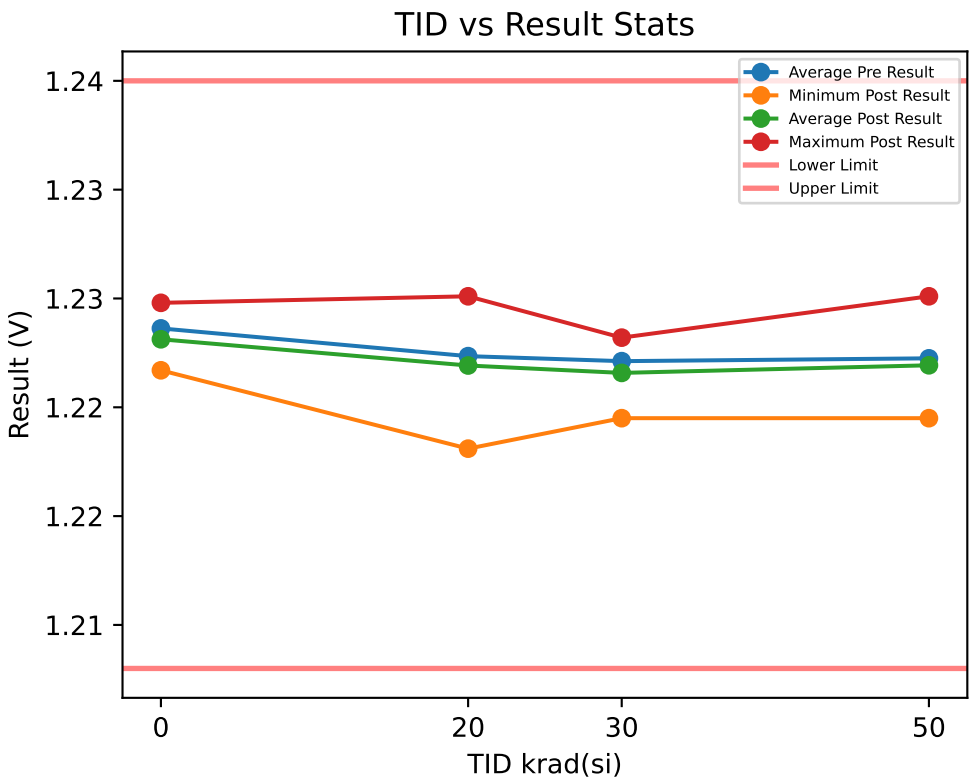
Test Results (Lower Limit = 1.208, Upper Limit = 1.235 (V))

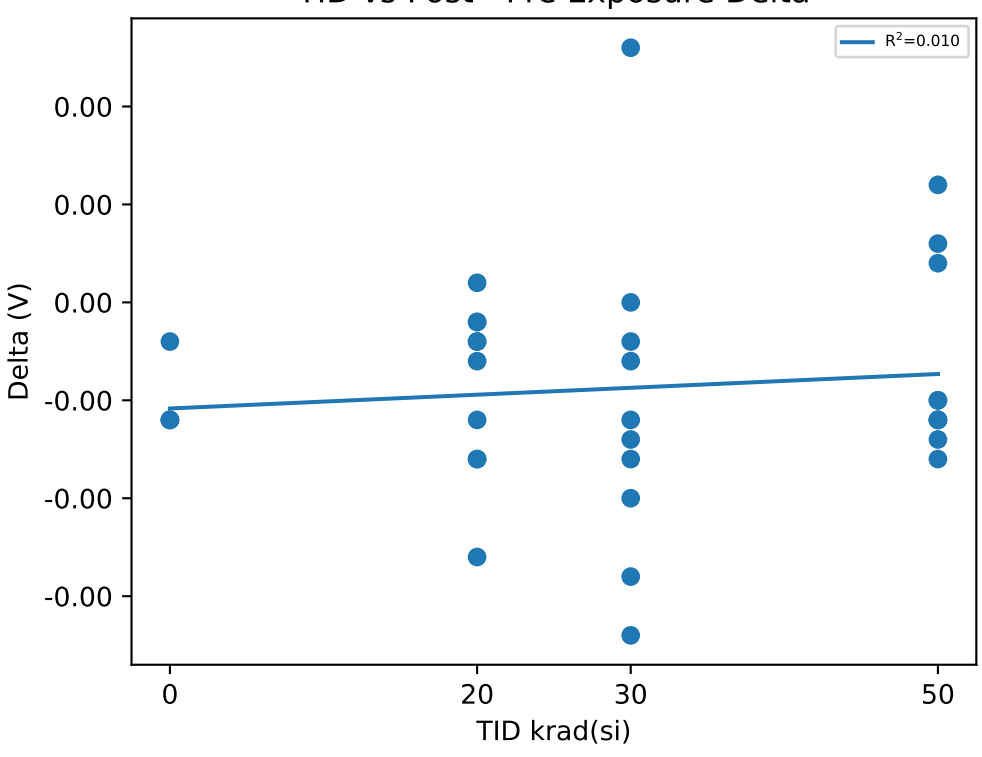
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	1.2218	1.2212	-0.0006
2	20	Unbiased	1.2235	1.2234	-0.0001
3	50	Biased	1.2247	1.2239	-0.0008
4	30	Unbiased	1.2221	1.2211	-0.001
5	50	Unbiased	1.2203	1.2198	-0.0005
6	30	Biased	1.2212	1.2206	-0.0006
7	50	Biased	1.222	1.2213	-0.0007
8	30	Unbiased	1.2211	1.2195	-0.0016
9	20	Unbiased	1.2204	1.2201	-0.0003
10	50	Biased	1.2199	1.2194	-0.0005
11	30	Biased	1.2216	1.2213	-0.0003
12	0	Correlation	1.2236	1.223	-0.0006
13	0	Correlation	1.2254	1.2247	-0.0007
14	50	Unbiased	1.2203	1.2197	-0.0006
15	20	Biased	1.2203	1.2201	-0.0002
16	20	Unbiased	1.2249	1.2241	-0.0008
17	20	Biased	1.2216	1.2209	-0.0007
18	20	Unbiased	1.2244	1.2231	-0.0013
19	20	Biased	1.2215	1.2214	-0.0001
20	50	Unbiased	1.2251	1.2245	-0.0006
21	0	Correlation	1.2223	1.2216	-0.0007
22	50	Unbiased	1.2244	1.225	0.0006
23	0	Correlation	1.2231	1.223	-0.0001
24	20	Biased	1.2232	1.2225	-0.0007
26	50	Biased	1.2205	1.2208	0.0003
27	30	Unbiased	1.2213	1.2212	-0.0001
28	30	Biased	1.2246	1.2232	-0.0014
29	30	Unbiased	1.2238	1.2229	-0.0009
30	20	Biased	1.2179	1.218	0.0001
31	30	Unbiased	1.2209	1.2208	-0.0001
33	30	Biased	1.2235	1.2228	-0.0007
34	50	Unbiased	1.2227	1.223	0.0003
35	20	Unbiased	1.2252	1.225	-0.0002
41	30	Biased	1.2205	1.2219	0.0014

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2223	1.2236	1.2254	0.001314	1.2216	1.2231	1.2247	0.0012685	-0.0007	-0.000525	-0.0001	0.00028723
20	1.2179	1.2223	1.2252	0.0023553	1.218	1.2219	1.225	0.0021454	-0.0013	-0.00043	0.0001	0.0004296
30	1.2205	1.2221	1.2246	0.0014057	1.2195	1.2215	1.2232	0.0011681	-0.0016	-0.00053	0.0014	0.00084597
50	1.2199	1.2222	1.2251	0.0019816	1.2194	1.2219	1.225	0.002085	-0.0008	-0.00031	0.0006	0.00050431

Device Test: 21.37 VOLTAGE|VREF/VREF/12/12/0/1000/5/500kHz//@V_REFCAP





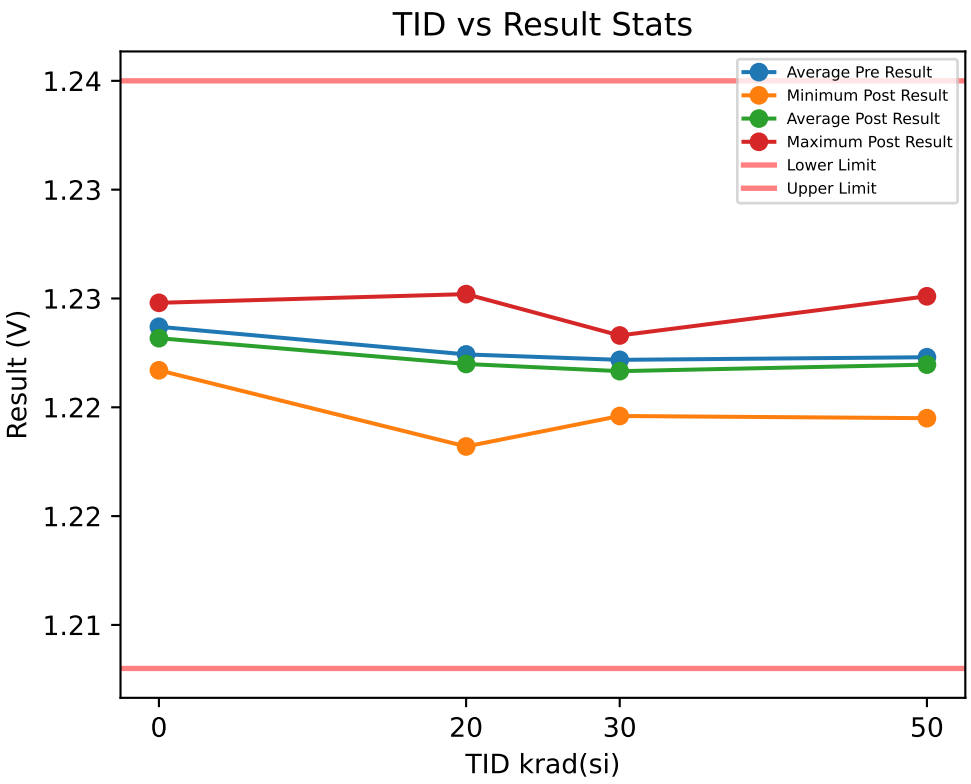
Test Results (Lower Limit = 1.208, Upper Limit = 1.235 (V))

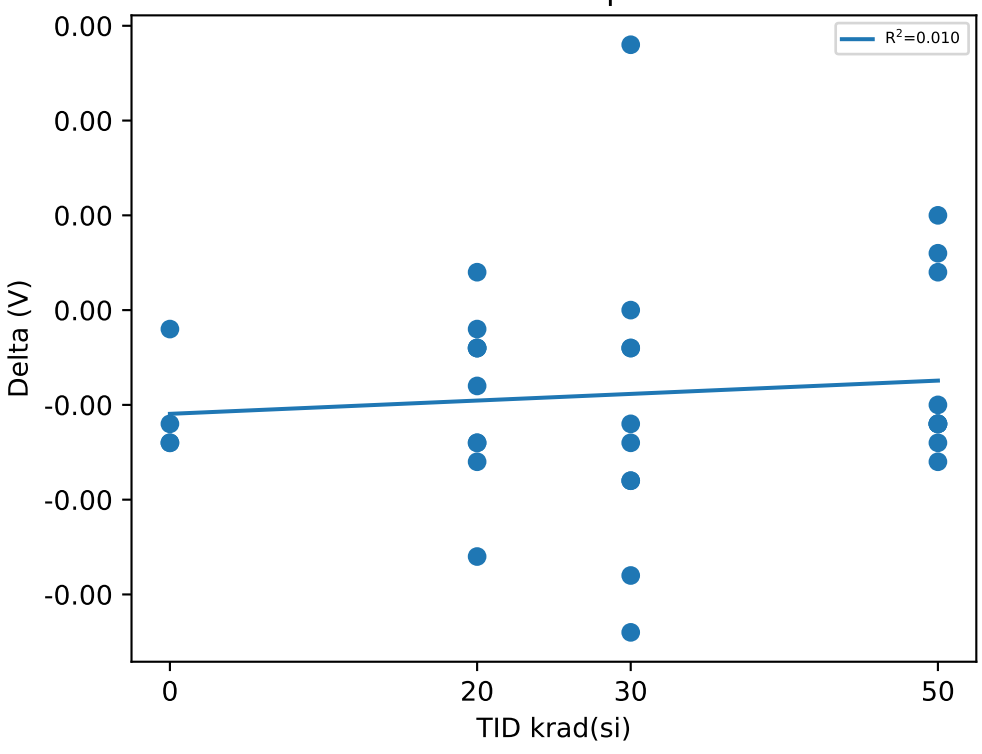
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	1.2218	1.2212	-0.0006
2	20	Unbiased	1.2236	1.2235	-0.0001
3	50	Biased	1.2248	1.224	-0.0008
4	30	Unbiased	1.2222	1.2212	-0.001
5	50	Unbiased	1.2204	1.2198	-0.0006
6	30	Biased	1.2213	1.2207	-0.0006
7	50	Biased	1.2221	1.2214	-0.0007
8	30	Unbiased	1.2212	1.2195	-0.0017
9	20	Unbiased	1.2205	1.2202	-0.0003
10	50	Biased	1.22	1.2195	-0.0005
11	30	Biased	1.2217	1.2214	-0.0003
12	0	Correlation	1.2236	1.223	-0.0006
13	0	Correlation	1.2254	1.2248	-0.0006
14	50	Unbiased	1.2204	1.2198	-0.0006
15	20	Biased	1.2203	1.2201	-0.0002
16	20	Unbiased	1.225	1.2242	-0.0008
17	20	Biased	1.2216	1.221	-0.0006
18	20	Unbiased	1.2244	1.2231	-0.0013
19	20	Biased	1.2215	1.2214	-0.0001
20	50	Unbiased	1.2251	1.2246	-0.0005
21	0	Correlation	1.2223	1.2217	-0.0006
22	50	Unbiased	1.2245	1.2251	0.0006
23	0	Correlation	1.2232	1.223	-0.0002
24	20	Biased	1.2233	1.2225	-0.0008
26	50	Biased	1.2206	1.2209	0.0003
27	30	Unbiased	1.2213	1.2213	0
28	30	Biased	1.2246	1.2232	-0.0014
29	30	Unbiased	1.2238	1.223	-0.0008
30	20	Biased	1.218	1.2181	0.0001
31	30	Unbiased	1.221	1.2208	-0.0002
33	30	Biased	1.2235	1.2228	-0.0007
34	50	Unbiased	1.2228	1.223	0.0002
35	20	Unbiased	1.2253	1.2251	-0.0002
41	30	Biased	1.2206	1.2219	0.0013

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2223	1.2236	1.2254	0.0013022	1.2217	1.2231	1.2248	0.0012738	-0.0006	-0.0005	-0.0002	0.0002
20	1.218	1.2224	1.2253	0.0023623	1.2181	1.2219	1.2251	0.0021478	-0.0013	-0.00043	0.0001	0.00043218
30	1.2206	1.2221	1.2246	0.0013669	1.2195	1.2216	1.2232	0.0011641	-0.0017	-0.00054	0.0013	0.00083293
50	1.22	1.2223	1.2251	0.0019677	1.2195	1.2219	1.2251	0.0020939	-0.0008	-0.00032	0.0006	0.00049171

Device Test: 21.39 VOLTAGE|VREF/VREF/14/14/0/1000/5/500kHz//@V_REFCAP





Test Results (Lower Limit = 1.208, Upper Limit = 1.235 (V))

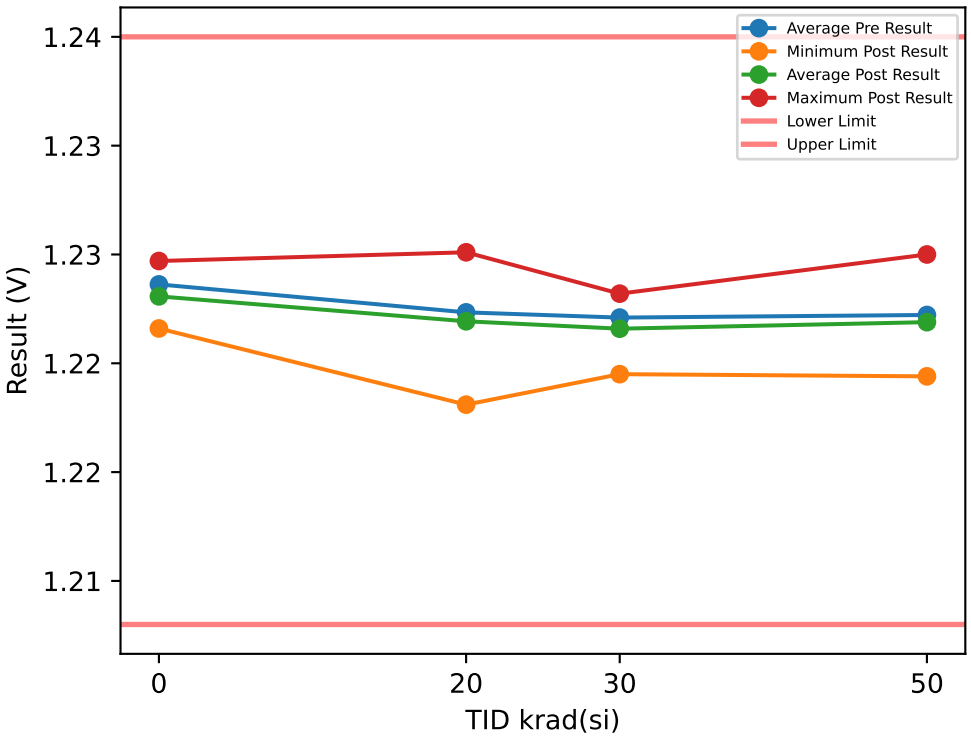
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	1.2219	1.2213	-0.0006
2	20	Unbiased	1.2237	1.2235	-0.0002
3	50	Biased	1.2248	1.224	-0.0008
4	30	Unbiased	1.2222	1.2213	-0.0009
5	50	Unbiased	1.2204	1.2198	-0.0006
6	30	Biased	1.2213	1.2207	-0.0006
7	50	Biased	1.2221	1.2214	-0.0007
8	30	Unbiased	1.2213	1.2196	-0.0017
9	20	Unbiased	1.2206	1.2202	-0.0004
10	50	Biased	1.2201	1.2195	-0.0006
11	30	Biased	1.2217	1.2215	-0.0002
12	0	Correlation	1.2237	1.2231	-0.0006
13	0	Correlation	1.2255	1.2248	-0.0007
14	50	Unbiased	1.2204	1.2198	-0.0006
15	20	Biased	1.2204	1.2202	-0.0002
16	20	Unbiased	1.2251	1.2243	-0.0008
17	20	Biased	1.2217	1.221	-0.0007
18	20	Unbiased	1.2245	1.2232	-0.0013
19	20	Biased	1.2216	1.2215	-0.0001
20	50	Unbiased	1.2252	1.2247	-0.0005
21	0	Correlation	1.2224	1.2217	-0.0007
22	50	Unbiased	1.2246	1.2251	0.0005
23	0	Correlation	1.2232	1.2231	-0.0001
24	20	Biased	1.2233	1.2226	-0.0007
26	50	Biased	1.2207	1.2209	0.0002
27	30	Unbiased	1.2214	1.2214	0
28	30	Biased	1.2247	1.2233	-0.0014
29	30	Unbiased	1.2239	1.223	-0.0009
30	20	Biased	1.218	1.2182	0.0002
31	30	Unbiased	1.2211	1.2209	-0.0002
33	30	Biased	1.2236	1.2229	-0.0007
34	50	Unbiased	1.2228	1.2231	0.0003
35	20	Unbiased	1.2254	1.2252	-0.0002
41	30	Biased	1.2206	1.222	0.0014

Test Statistics (V)

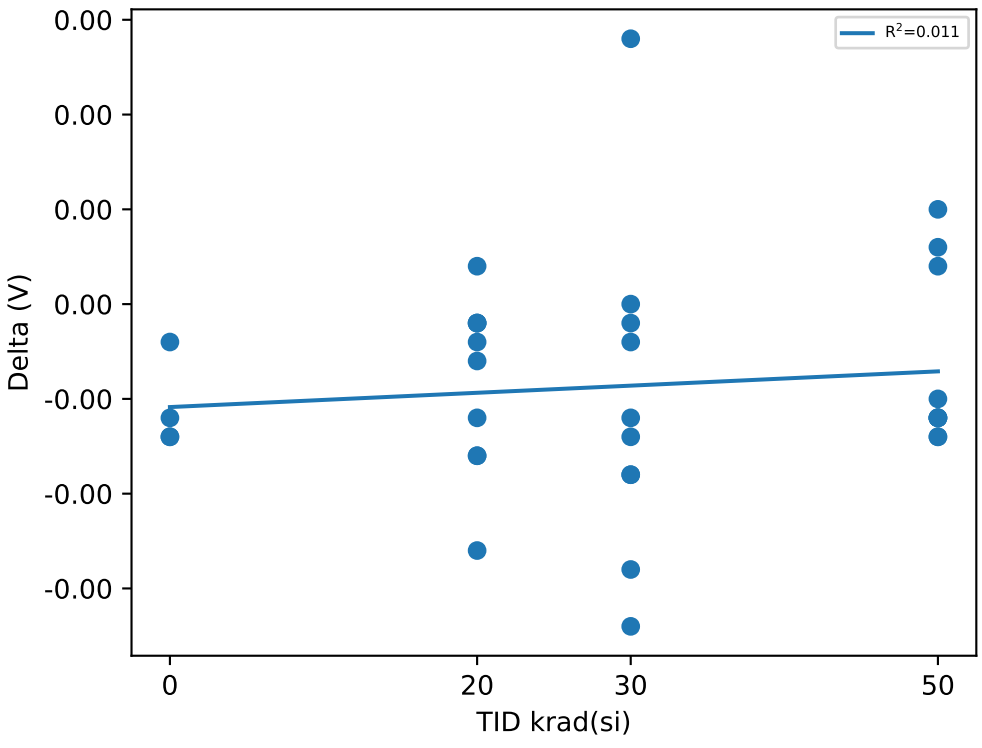
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2224	1.2237	1.2255	0.001314	1.2217	1.2232	1.2248	0.0012685	-0.0007	-0.000525	-0.0001	0.00028723
20	1.218	1.2224	1.2254	0.0023786	1.2182	1.222	1.2252	0.0021538	-0.0013	-0.00044	0.0002	0.00043512
30	1.2206	1.2222	1.2247	0.0013895	1.2196	1.2217	1.2233	0.0011597	-0.0017	-0.00052	0.0014	0.00085997
50	1.2201	1.2223	1.2252	0.0019726	1.2195	1.222	1.2251	0.0021104	-0.0008	-0.00034	0.0005	0.00047656

Device Test: 21.41 VOLTAGE|VREF/VREF/4.5/4.5/0/1000/4.5/1MHz//@V_REFCAP

TID vs Result Stats



TID vs Post - Pre Exposure Delta



Test Results (Lower Limit = 1.208, Upper Limit = 1.235 (V))

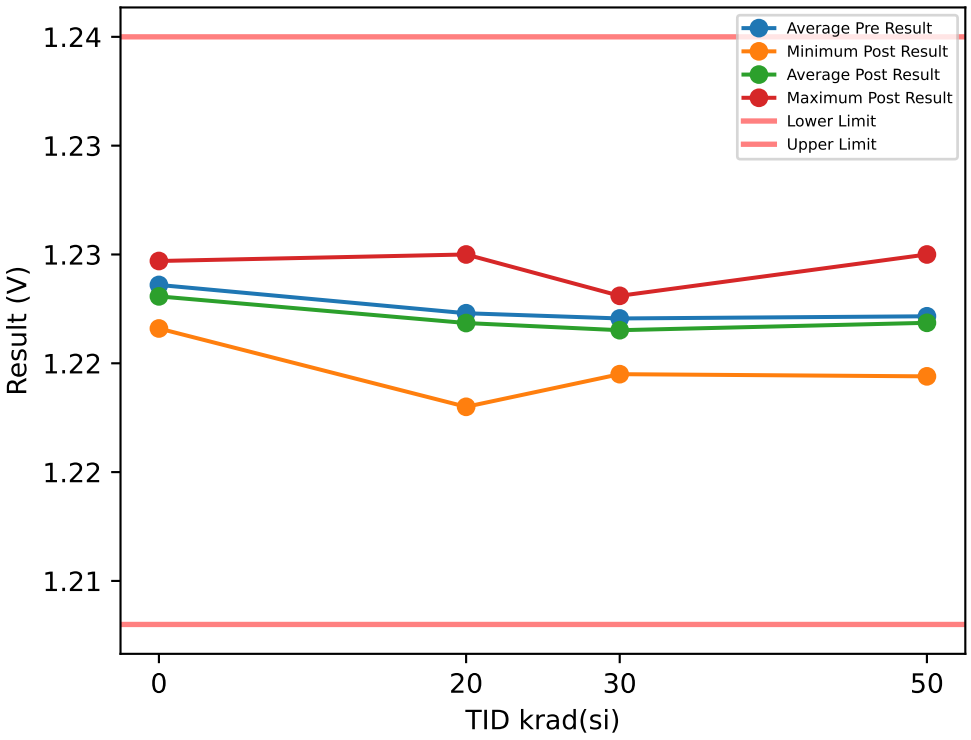
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	1.2218	1.2212	-0.0006
2	20	Unbiased	1.2236	1.2235	-0.0001
3	50	Biased	1.2247	1.224	-0.0007
4	30	Unbiased	1.2221	1.2212	-0.0009
5	50	Unbiased	1.2204	1.2198	-0.0006
6	30	Biased	1.2213	1.2207	-0.0006
7	50	Biased	1.222	1.2213	-0.0007
8	30	Unbiased	1.2212	1.2195	-0.0017
9	20	Unbiased	1.2205	1.2202	-0.0003
10	50	Biased	1.22	1.2194	-0.0006
11	30	Biased	1.2216	1.2214	-0.0002
12	0	Correlation	1.2236	1.223	-0.0006
13	0	Correlation	1.2254	1.2247	-0.0007
14	50	Unbiased	1.2204	1.2198	-0.0006
15	20	Biased	1.2203	1.2202	-0.0001
16	20	Unbiased	1.225	1.2242	-0.0008
17	20	Biased	1.2216	1.221	-0.0006
18	20	Unbiased	1.2244	1.2231	-0.0013
19	20	Biased	1.2215	1.2214	-0.0001
20	50	Unbiased	1.2251	1.2246	-0.0005
21	0	Correlation	1.2223	1.2216	-0.0007
22	50	Unbiased	1.2245	1.225	0.0005
23	0	Correlation	1.2232	1.223	-0.0002
24	20	Biased	1.2233	1.2225	-0.0008
26	50	Biased	1.2206	1.2208	0.0002
27	30	Unbiased	1.2213	1.2213	0
28	30	Biased	1.2246	1.2232	-0.0014
29	30	Unbiased	1.2238	1.2229	-0.0009
30	20	Biased	1.2179	1.2181	0.0002
31	30	Unbiased	1.221	1.2209	-0.0001
33	30	Biased	1.2235	1.2228	-0.0007
34	50	Unbiased	1.2227	1.223	0.0003
35	20	Unbiased	1.2253	1.2251	-0.0002
41	30	Biased	1.2206	1.222	0.0014

Test Statistics (V)

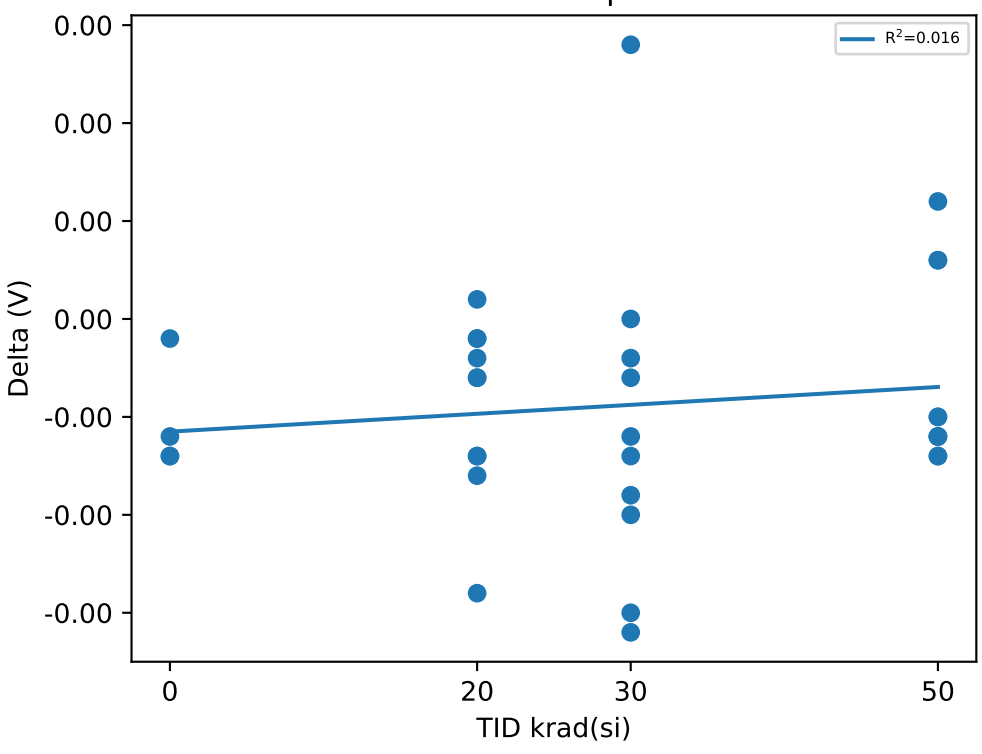
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2223	1.2236	1.2254	0.0013022	1.2216	1.2231	1.2247	0.0012685	-0.0007	-0.00055	-0.0002	0.00023805
20	1.2179	1.2223	1.2253	0.0023829	1.2181	1.2219	1.2251	0.0021386	-0.0013	-0.00041	0.0002	0.00045326
30	1.2206	1.2221	1.2246	0.0013703	1.2195	1.2216	1.2232	0.0011474	-0.0017	-0.00051	0.0014	0.00086468
50	1.22	1.2222	1.2251	0.0019515	1.2194	1.2219	1.225	0.0020989	-0.0007	-0.00033	0.0005	0.00046679

Device Test: 21.43 VOLTAGE|VREF/VREF/5/5/0/1000/5/1MHz//@V_REFCAP

TID vs Result Stats



TID vs Post - Pre Exposure Delta



Test Results (Lower Limit = 1.208, Upper Limit = 1.235 (V))

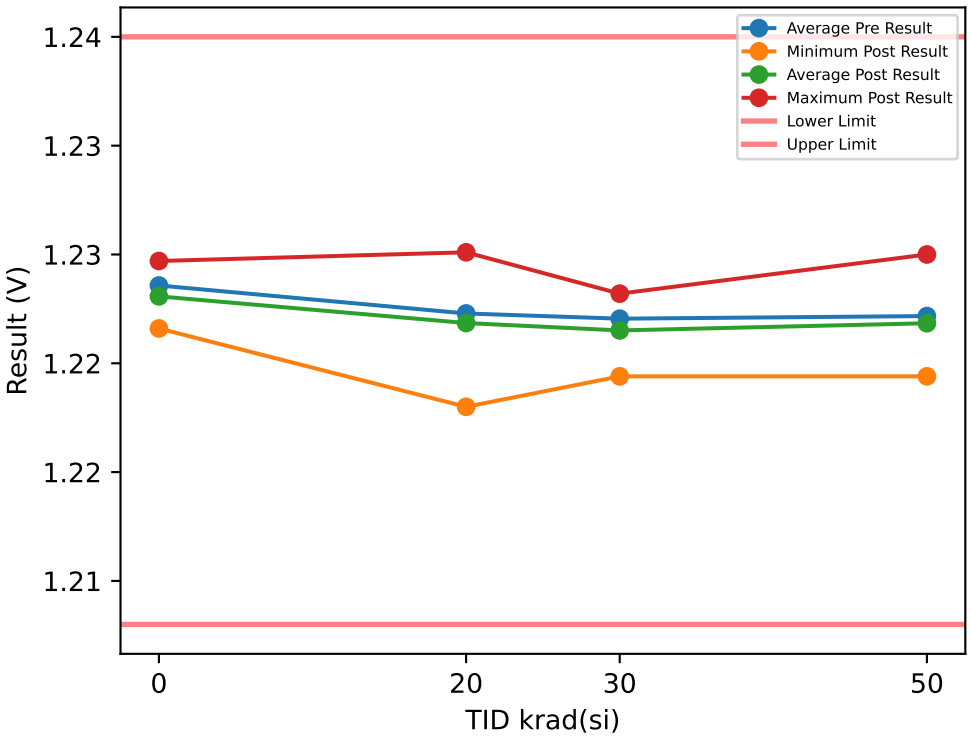
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	1.2218	1.2212	-0.0006
2	20	Unbiased	1.2235	1.2234	-0.0001
3	50	Biased	1.2247	1.224	-0.0007
4	30	Unbiased	1.2221	1.2211	-0.001
5	50	Unbiased	1.2203	1.2197	-0.0006
6	30	Biased	1.2212	1.2206	-0.0006
7	50	Biased	1.222	1.2213	-0.0007
8	30	Unbiased	1.2211	1.2195	-0.0016
9	20	Unbiased	1.2204	1.2201	-0.0003
10	50	Biased	1.2199	1.2194	-0.0005
11	30	Biased	1.2216	1.2213	-0.0003
12	0	Correlation	1.2236	1.223	-0.0006
13	0	Correlation	1.2254	1.2247	-0.0007
14	50	Unbiased	1.2203	1.2197	-0.0006
15	20	Biased	1.2203	1.2201	-0.0002
16	20	Unbiased	1.2249	1.2241	-0.0008
17	20	Biased	1.2216	1.2209	-0.0007
18	20	Unbiased	1.2244	1.223	-0.0014
19	20	Biased	1.2215	1.2214	-0.0001
20	50	Unbiased	1.225	1.2245	-0.0005
21	0	Correlation	1.2223	1.2216	-0.0007
22	50	Unbiased	1.2244	1.225	0.0006
23	0	Correlation	1.2231	1.223	-0.0001
24	20	Biased	1.2232	1.2225	-0.0007
26	50	Biased	1.2205	1.2208	0.0003
27	30	Unbiased	1.2212	1.2212	0
28	30	Biased	1.2246	1.2231	-0.0015
29	30	Unbiased	1.2238	1.2229	-0.0009
30	20	Biased	1.2179	1.218	0.0001
31	30	Unbiased	1.221	1.2208	-0.0002
33	30	Biased	1.2235	1.2228	-0.0007
34	50	Unbiased	1.2227	1.223	0.0003
35	20	Unbiased	1.2253	1.225	-0.0003
41	30	Biased	1.2205	1.2219	0.0014

Test Statistics (V)

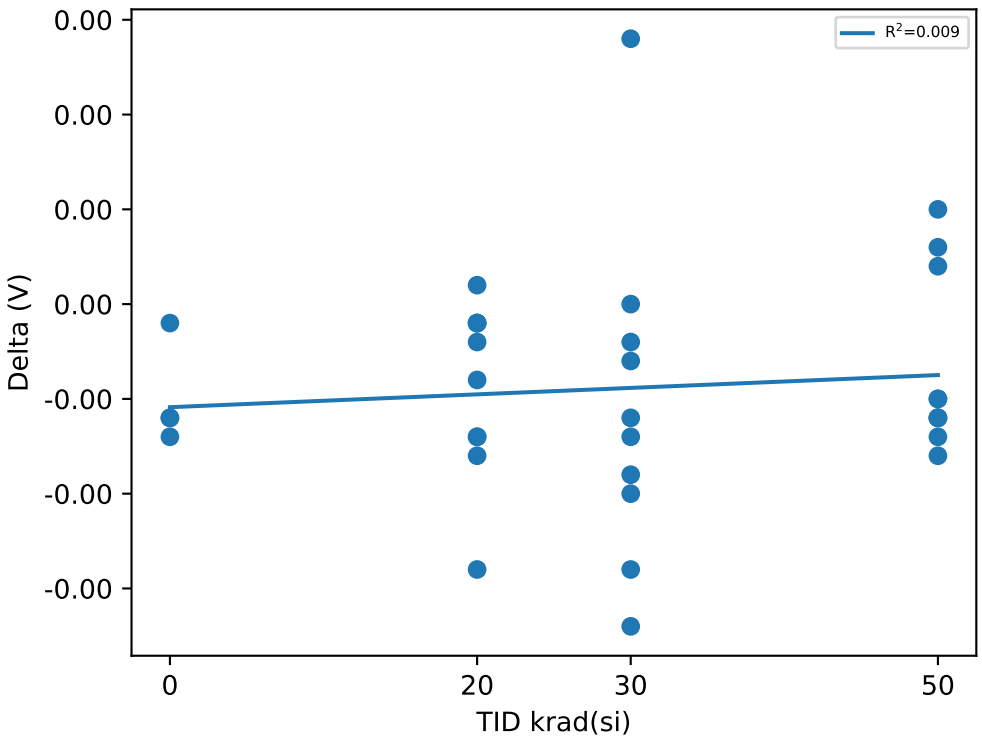
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2223	1.2236	1.2254	0.001314	1.2216	1.2231	1.2247	0.0012685	-0.0007	-0.000525	-0.0001	0.00028723
20	1.2179	1.2223	1.2253	0.0023692	1.218	1.2219	1.225	0.0021392	-0.0014	-0.00045	0.0001	0.00044783
30	1.2205	1.2221	1.2246	0.0014033	1.2195	1.2215	1.2231	0.0011526	-0.0016	-0.00054	0.0014	0.0008592
50	1.2199	1.2222	1.225	0.0019654	1.2194	1.2219	1.225	0.0021072	-0.0007	-0.0003	0.0006	0.00049441

Device Test: 21.45 VOLTAGE|VREF/VREF/12/12/0/1000/5/1MHz//@V_REFCAP

TID vs Result Stats



TID vs Post - Pre Exposure Delta



Test Results (Lower Limit = 1.208, Upper Limit = 1.235 (V))

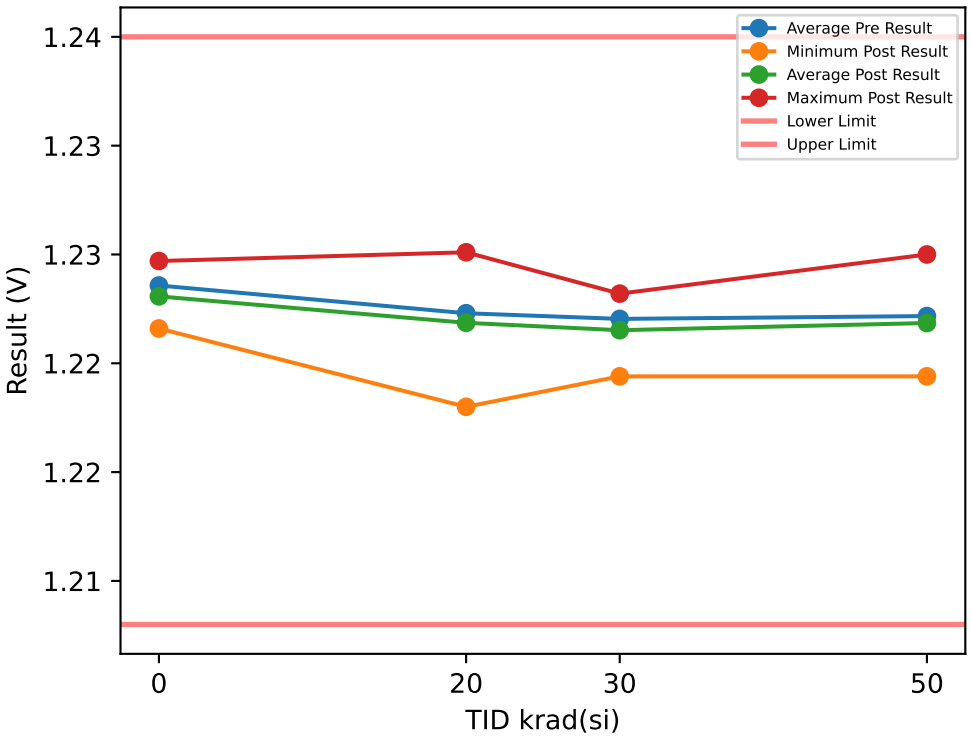
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	1.2217	1.2211	-0.0006
2	20	Unbiased	1.2235	1.2234	-0.0001
3	50	Biased	1.2247	1.2239	-0.0008
4	30	Unbiased	1.2221	1.2211	-0.001
5	50	Unbiased	1.2203	1.2197	-0.0006
6	30	Biased	1.2212	1.2206	-0.0006
7	50	Biased	1.222	1.2213	-0.0007
8	30	Unbiased	1.2211	1.2194	-0.0017
9	20	Unbiased	1.2205	1.2201	-0.0004
10	50	Biased	1.2199	1.2194	-0.0005
11	30	Biased	1.2216	1.2213	-0.0003
12	0	Correlation	1.2236	1.223	-0.0006
13	0	Correlation	1.2254	1.2247	-0.0007
14	50	Unbiased	1.2203	1.2197	-0.0006
15	20	Biased	1.2202	1.2201	-0.0001
16	20	Unbiased	1.2249	1.2241	-0.0008
17	20	Biased	1.2216	1.2209	-0.0007
18	20	Unbiased	1.2244	1.223	-0.0014
19	20	Biased	1.2214	1.2213	-0.0001
20	50	Unbiased	1.225	1.2245	-0.0005
21	0	Correlation	1.2222	1.2216	-0.0006
22	50	Unbiased	1.2245	1.225	0.0005
23	0	Correlation	1.2231	1.223	-0.0001
24	20	Biased	1.2232	1.2225	-0.0007
26	50	Biased	1.2205	1.2208	0.0003
27	30	Unbiased	1.2213	1.2213	0
28	30	Biased	1.2246	1.2232	-0.0014
29	30	Unbiased	1.2238	1.2229	-0.0009
30	20	Biased	1.2179	1.218	0.0001
31	30	Unbiased	1.2209	1.2207	-0.0002
33	30	Biased	1.2234	1.2227	-0.0007
34	50	Unbiased	1.2228	1.223	0.0002
35	20	Unbiased	1.2253	1.2251	-0.0002
41	30	Biased	1.2205	1.2219	0.0014

Test Statistics (V)

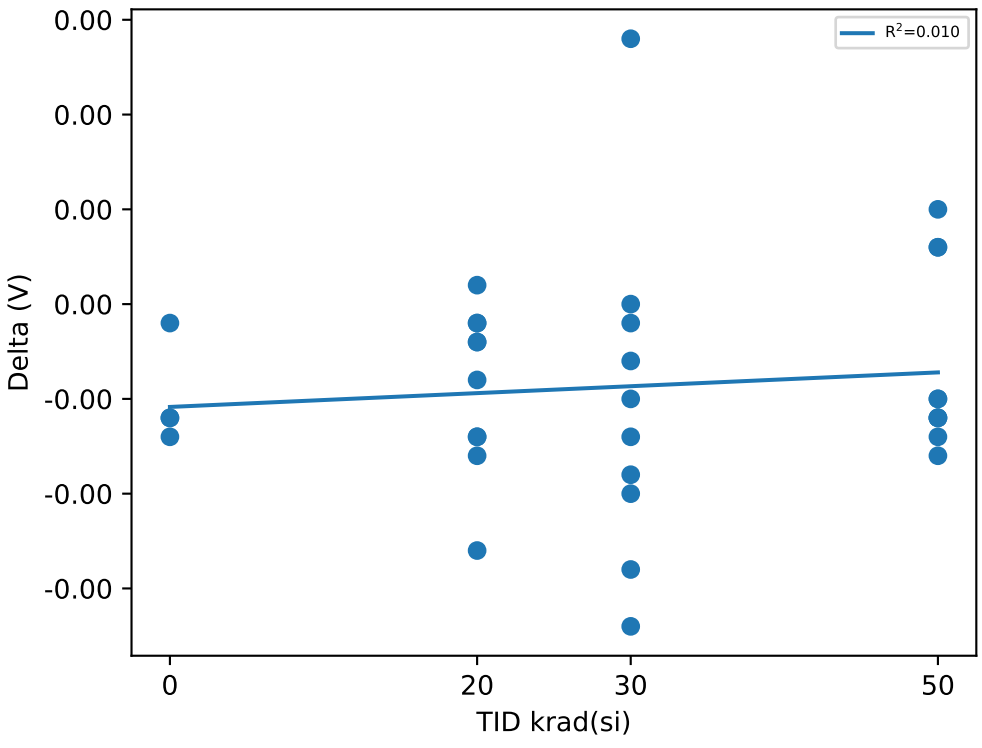
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2222	1.2236	1.2254	0.0013475	1.2216	1.2231	1.2247	0.0012685	-0.0007	-0.0005	-0.0001	0.0002708
20	1.2179	1.2223	1.2253	0.0023741	1.218	1.2219	1.2251	0.0021583	-0.0014	-0.00044	0.0001	0.00045753
30	1.2205	1.222	1.2246	0.0013946	1.2194	1.2215	1.2232	0.0011808	-0.0017	-0.00054	0.0014	0.00086178
50	1.2199	1.2222	1.225	0.0019839	1.2194	1.2218	1.225	0.0020998	-0.0008	-0.00033	0.0005	0.00047152

Device Test: 21.47 VOLTAGE|VREF/VREF/14/14/0/1000/5/1MHz//@V_REFCAP

TID vs Result Stats



TID vs Post - Pre Exposure Delta



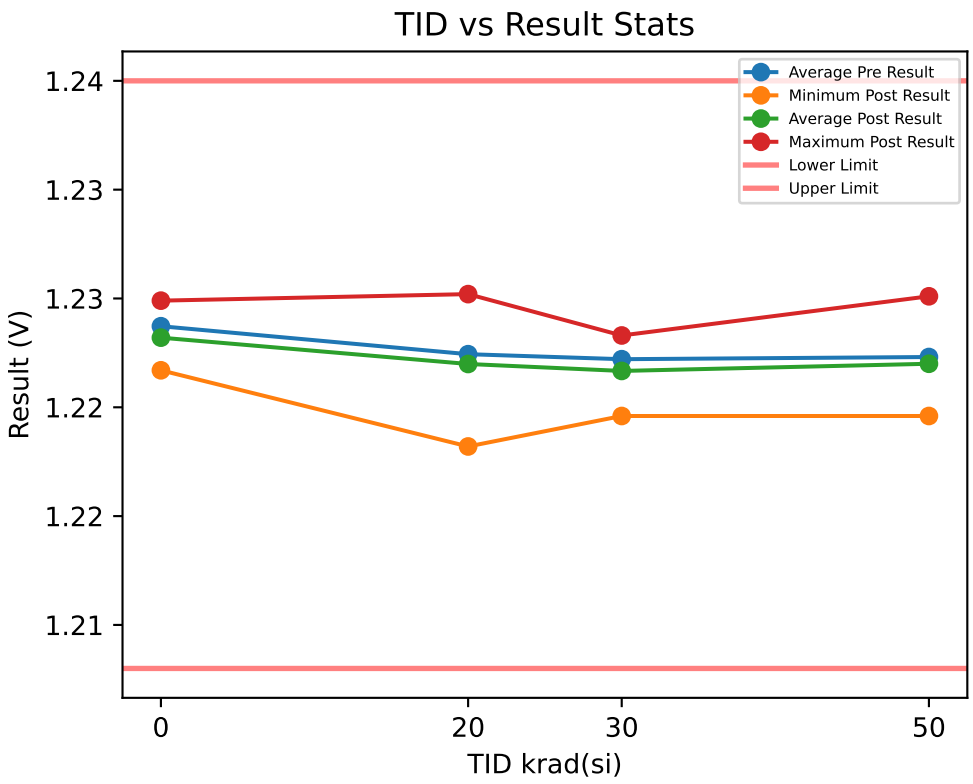
Test Results (Lower Limit = 1.208, Upper Limit = 1.235 (V))

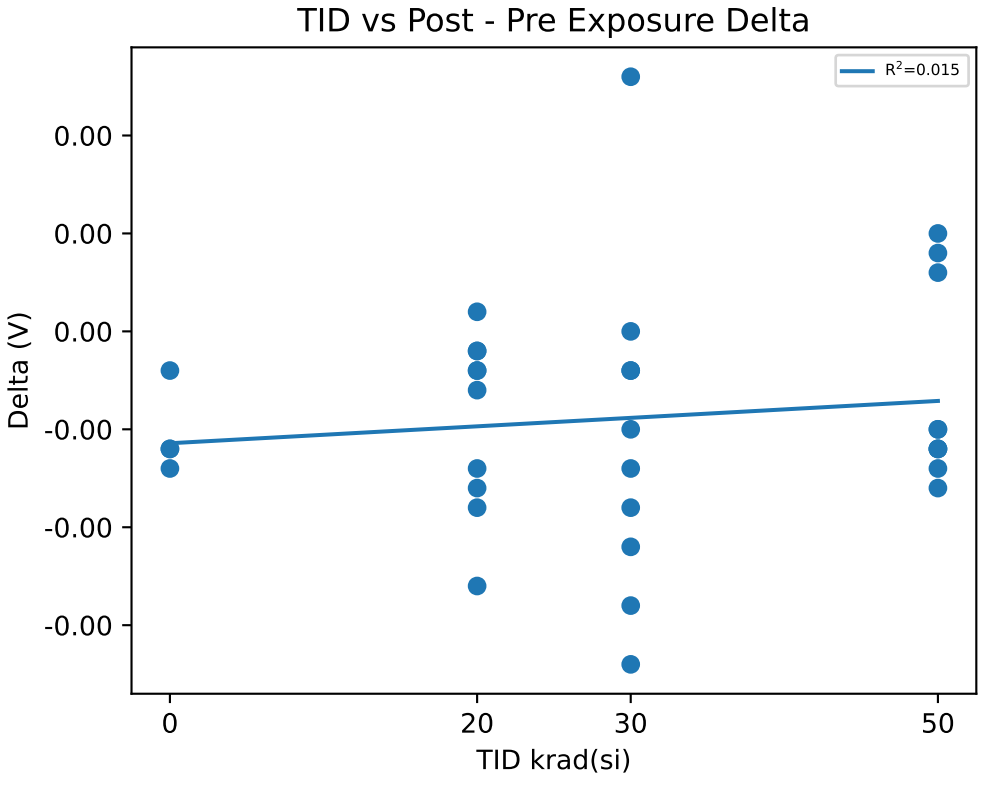
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	1.2217	1.2211	-0.0006
2	20	Unbiased	1.2235	1.2234	-0.0001
3	50	Biased	1.2247	1.2239	-0.0008
4	30	Unbiased	1.2221	1.2211	-0.001
5	50	Unbiased	1.2203	1.2197	-0.0006
6	30	Biased	1.2212	1.2207	-0.0005
7	50	Biased	1.222	1.2213	-0.0007
8	30	Unbiased	1.2211	1.2194	-0.0017
9	20	Unbiased	1.2205	1.2201	-0.0004
10	50	Biased	1.2199	1.2194	-0.0005
11	30	Biased	1.2216	1.2213	-0.0003
12	0	Correlation	1.2236	1.223	-0.0006
13	0	Correlation	1.2254	1.2247	-0.0007
14	50	Unbiased	1.2204	1.2198	-0.0006
15	20	Biased	1.2203	1.2201	-0.0002
16	20	Unbiased	1.2249	1.2241	-0.0008
17	20	Biased	1.2216	1.2209	-0.0007
18	20	Unbiased	1.2244	1.2231	-0.0013
19	20	Biased	1.2214	1.2213	-0.0001
20	50	Unbiased	1.225	1.2245	-0.0005
21	0	Correlation	1.2222	1.2216	-0.0006
22	50	Unbiased	1.2245	1.225	0.0005
23	0	Correlation	1.2231	1.223	-0.0001
24	20	Biased	1.2232	1.2225	-0.0007
26	50	Biased	1.2205	1.2208	0.0003
27	30	Unbiased	1.2213	1.2213	0
28	30	Biased	1.2246	1.2232	-0.0014
29	30	Unbiased	1.2237	1.2228	-0.0009
30	20	Biased	1.2179	1.218	0.0001
31	30	Unbiased	1.2209	1.2208	-0.0001
33	30	Biased	1.2234	1.2227	-0.0007
34	50	Unbiased	1.2227	1.223	0.0003
35	20	Unbiased	1.2253	1.2251	-0.0002
41	30	Biased	1.2205	1.2219	0.0014

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2222	1.2236	1.2254	0.0013475	1.2216	1.2231	1.2247	0.0012685	-0.0007	-0.0005	-0.0001	0.0002708
20	1.2179	1.2223	1.2253	0.0023646	1.218	1.2219	1.2251	0.0021645	-0.0013	-0.00044	0.0001	0.0004274
30	1.2205	1.222	1.2246	0.001381	1.2194	1.2215	1.2232	0.0011526	-0.0017	-0.00052	0.0014	0.00086641
50	1.2199	1.2222	1.225	0.0019704	1.2194	1.2219	1.225	0.0020887	-0.0008	-0.00032	0.0005	0.00048488

Device Test: 21.5 VOLTAGE|VREF/VREF/12/12/0/0/5/100kHz//@V_REFCAP





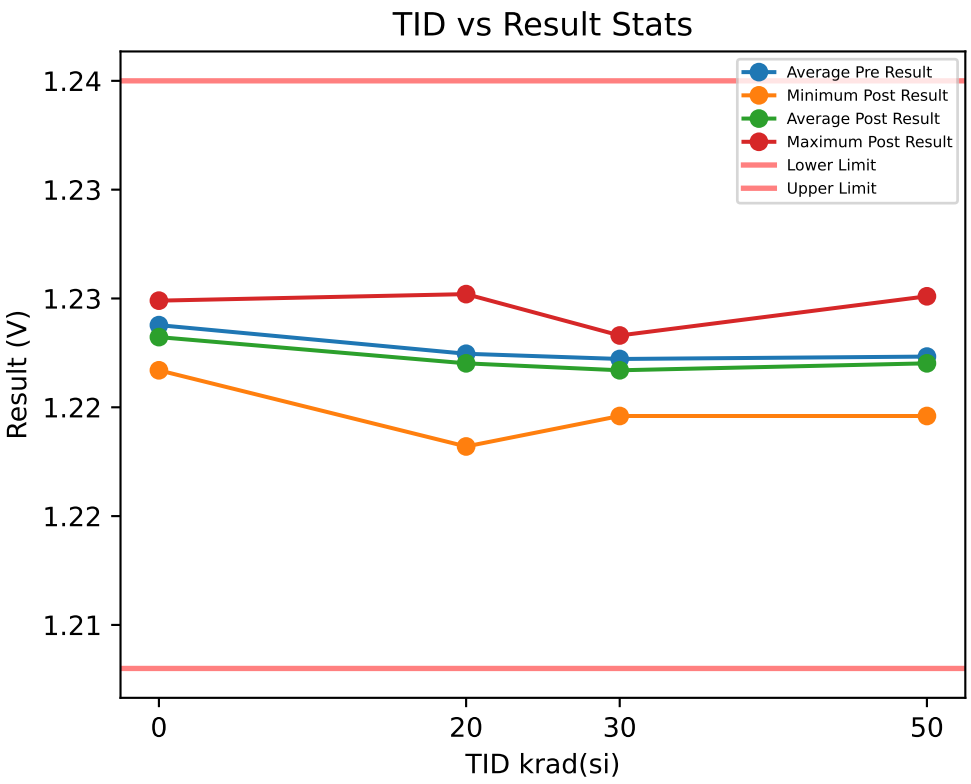
Test Results (Lower Limit = 1.208, Upper Limit = 1.235 (V))

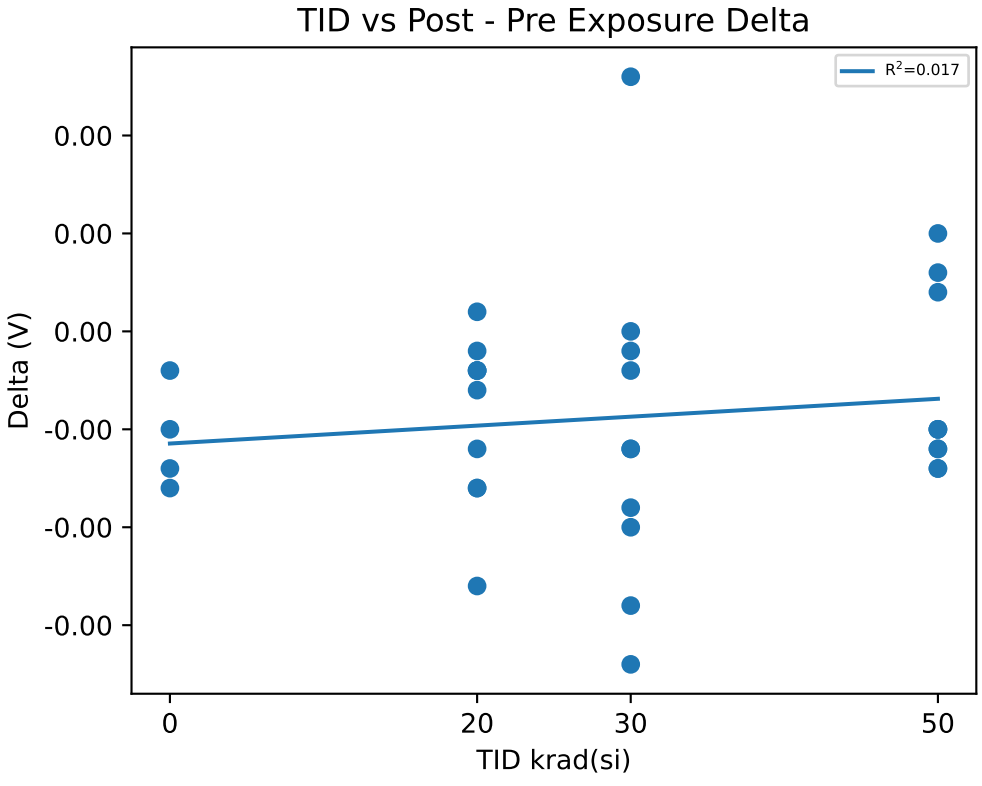
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	1.2219	1.2213	-0.0006
2	20	Unbiased	1.2236	1.2235	-0.0001
3	50	Biased	1.2248	1.2241	-0.0007
4	30	Unbiased	1.2223	1.2212	-0.0011
5	50	Unbiased	1.2205	1.2199	-0.0006
6	30	Biased	1.2213	1.2208	-0.0005
7	50	Biased	1.2222	1.2214	-0.0008
8	30	Unbiased	1.2213	1.2196	-0.0017
9	20	Unbiased	1.2206	1.2203	-0.0003
10	50	Biased	1.2201	1.2196	-0.0005
11	30	Biased	1.2217	1.2215	-0.0002
12	0	Correlation	1.2237	1.2231	-0.0006
13	0	Correlation	1.2255	1.2249	-0.0006
14	50	Unbiased	1.2204	1.2198	-0.0006
15	20	Biased	1.2204	1.2202	-0.0002
16	20	Unbiased	1.2251	1.2242	-0.0009
17	20	Biased	1.2217	1.221	-0.0007
18	20	Unbiased	1.2245	1.2232	-0.0013
19	20	Biased	1.2216	1.2215	-0.0001
20	50	Unbiased	1.2252	1.2247	-0.0005
21	0	Correlation	1.2224	1.2217	-0.0007
22	50	Unbiased	1.2246	1.2251	0.0005
23	0	Correlation	1.2233	1.2231	-0.0002
24	20	Biased	1.2234	1.2226	-0.0008
26	50	Biased	1.2206	1.221	0.0004
27	30	Unbiased	1.2214	1.2214	0
28	30	Biased	1.2247	1.2233	-0.0014
29	30	Unbiased	1.224	1.2231	-0.0009
30	20	Biased	1.2181	1.2182	0.0001
31	30	Unbiased	1.2211	1.2209	-0.0002
33	30	Biased	1.2236	1.2229	-0.0007
34	50	Unbiased	1.2228	1.2231	0.0003
35	20	Unbiased	1.2254	1.2252	-0.0002
41	30	Biased	1.2207	1.222	0.0013

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2224	1.2237	1.2255	0.0013022	1.2217	1.2232	1.2249	0.0013115	-0.0007	-0.000525	-0.0002	0.00022174
20	1.2181	1.2224	1.2254	0.0023566	1.2182	1.222	1.2252	0.002133	-0.0013	-0.00045	0.0001	0.00044783
30	1.2207	1.2222	1.2247	0.0013916	1.2196	1.2217	1.2233	0.0011681	-0.0017	-0.00054	0.0013	0.00084748
50	1.2201	1.2223	1.2252	0.0019706	1.2196	1.222	1.2251	0.0020918	-0.0008	-0.00031	0.0005	0.00049989

Device Test: 21.7 VOLTAGE|VREF/VREF/14/14/0/0/5/100kHz//@V_REFCAP





Test Results (Lower Limit = 1.208, Upper Limit = 1.235 (V))

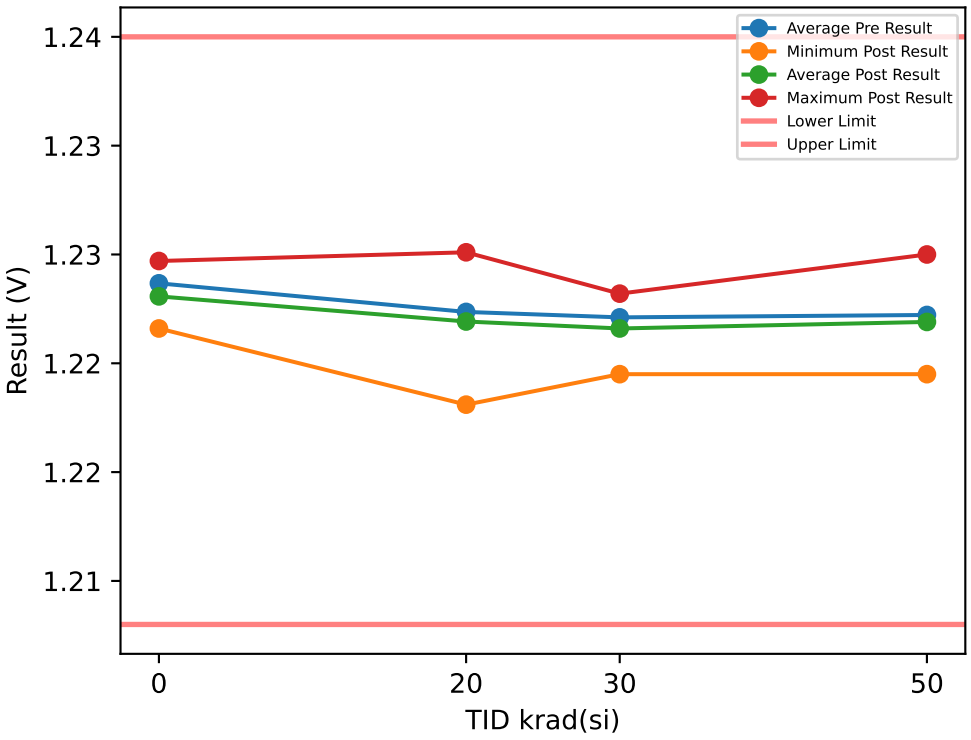
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	1.2219	1.2213	-0.0006
2	20	Unbiased	1.2237	1.2236	-0.0001
3	50	Biased	1.2248	1.2241	-0.0007
4	30	Unbiased	1.2223	1.2213	-0.001
5	50	Unbiased	1.2205	1.2199	-0.0006
6	30	Biased	1.2214	1.2208	-0.0006
7	50	Biased	1.2222	1.2215	-0.0007
8	30	Unbiased	1.2213	1.2196	-0.0017
9	20	Unbiased	1.2206	1.2203	-0.0003
10	50	Biased	1.2201	1.2196	-0.0005
11	30	Biased	1.2217	1.2215	-0.0002
12	0	Correlation	1.2237	1.2232	-0.0005
13	0	Correlation	1.2256	1.2249	-0.0007
14	50	Unbiased	1.2204	1.2199	-0.0005
15	20	Biased	1.2204	1.2202	-0.0002
16	20	Unbiased	1.2251	1.2243	-0.0008
17	20	Biased	1.2217	1.2211	-0.0006
18	20	Unbiased	1.2245	1.2232	-0.0013
19	20	Biased	1.2217	1.2215	-0.0002
20	50	Unbiased	1.2252	1.2247	-0.0005
21	0	Correlation	1.2225	1.2217	-0.0008
22	50	Unbiased	1.2246	1.2251	0.0005
23	0	Correlation	1.2233	1.2231	-0.0002
24	20	Biased	1.2234	1.2226	-0.0008
26	50	Biased	1.2207	1.221	0.0003
27	30	Unbiased	1.2214	1.2214	0
28	30	Biased	1.2247	1.2233	-0.0014
29	30	Unbiased	1.224	1.2231	-0.0009
30	20	Biased	1.2181	1.2182	0.0001
31	30	Unbiased	1.2211	1.221	-0.0001
33	30	Biased	1.2236	1.223	-0.0006
34	50	Unbiased	1.2229	1.2231	0.0002
35	20	Unbiased	1.2254	1.2252	-0.0002
41	30	Biased	1.2207	1.222	0.0013

Test Statistics (V)

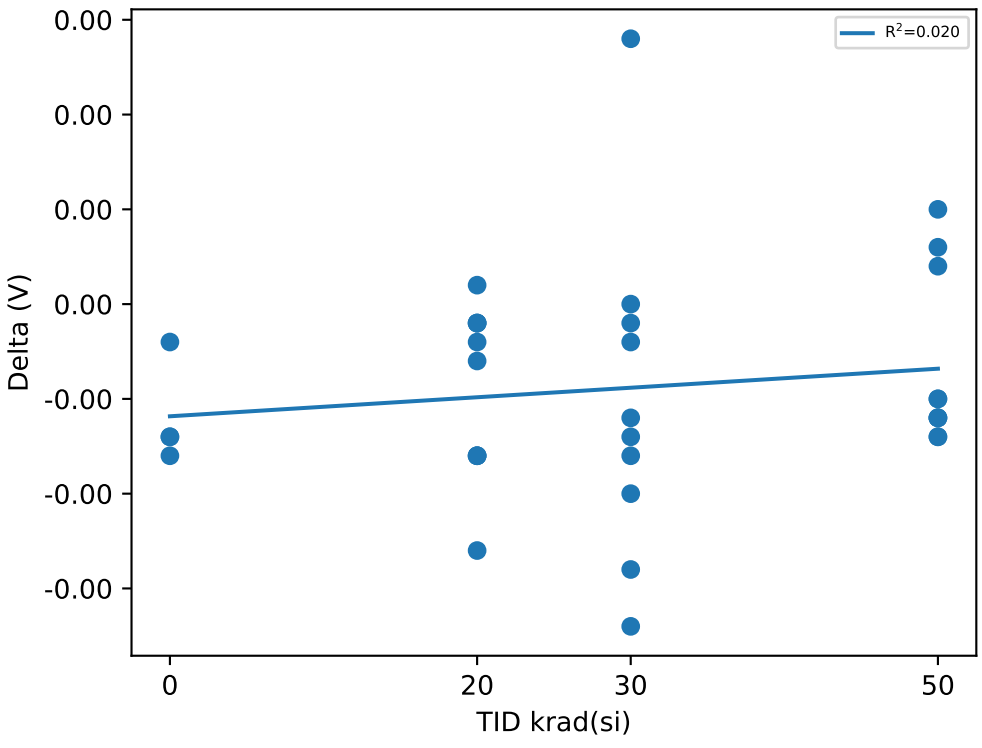
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2225	1.2238	1.2256	0.001315	1.2217	1.2232	1.2249	0.0013099	-0.0008	-0.00055	-0.0002	0.00026458
20	1.2181	1.2225	1.2254	0.0023585	1.2182	1.222	1.2252	0.0021478	-0.0013	-0.00044	0.0001	0.00042479
30	1.2207	1.2222	1.2247	0.0013847	1.2196	1.2217	1.2233	0.001169	-0.0017	-0.00052	0.0013	0.00084433
50	1.2201	1.2223	1.2252	0.0019642	1.2196	1.222	1.2251	0.0020773	-0.0007	-0.00031	0.0005	0.0004557

Device Test: 21.9 VOLTAGE|VREF/VREF/4.5/4.5/0/0/4.5/500kHz//@V_REFCAP

TID vs Result Stats



TID vs Post - Pre Exposure Delta



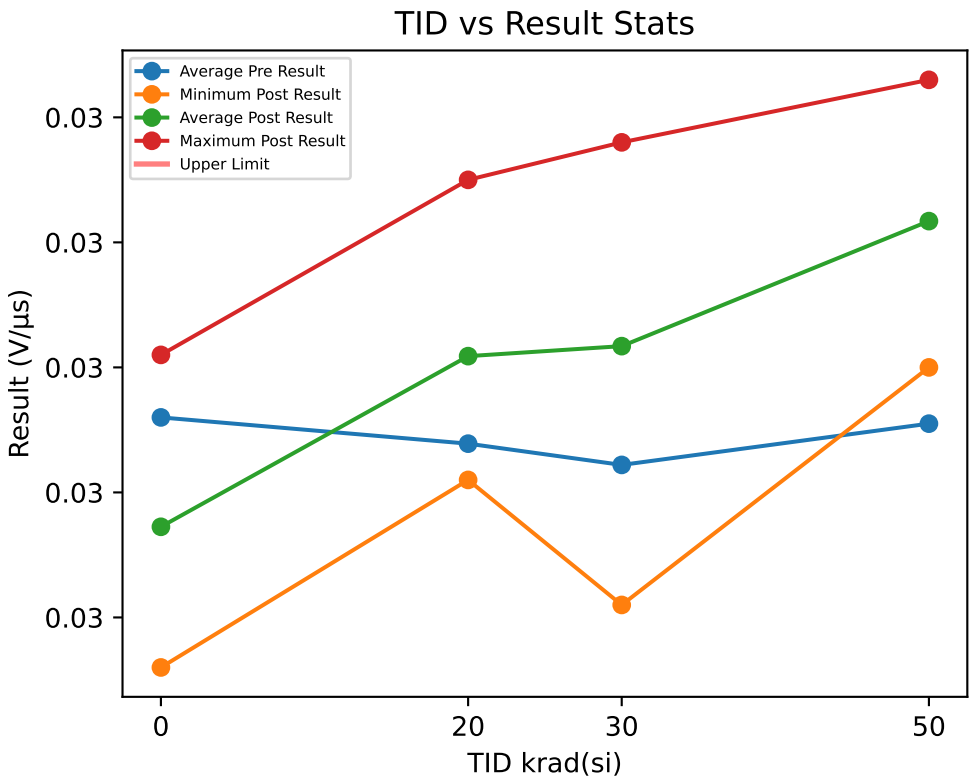
Test Results (Lower Limit = 1.208, Upper Limit = 1.235 (V))

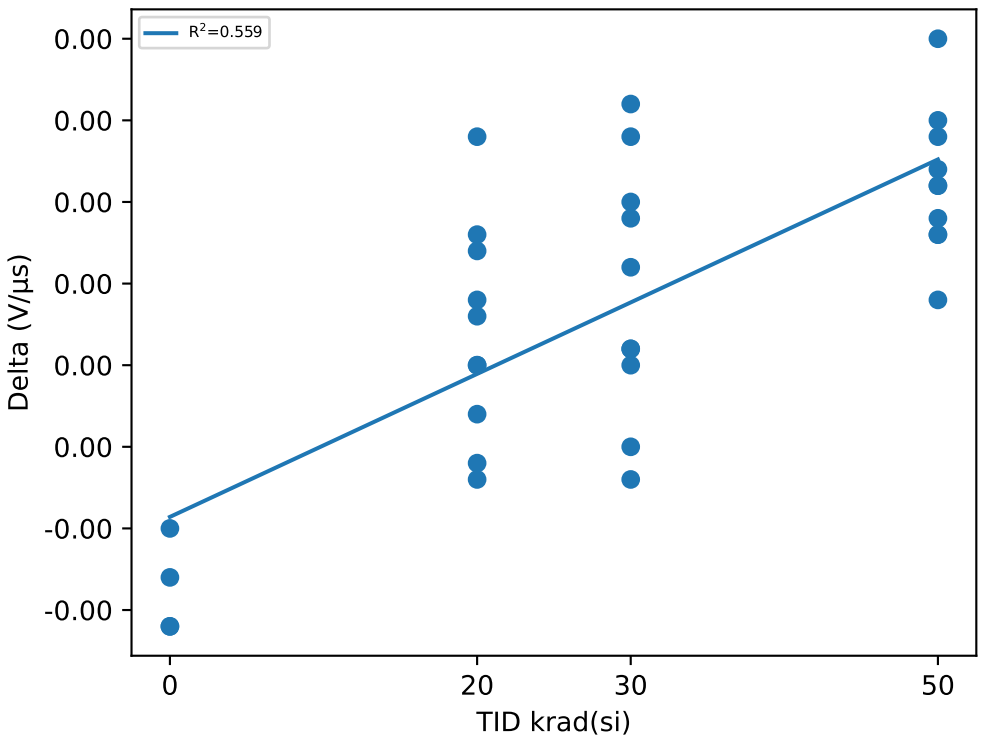
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	1.2218	1.2212	-0.0006
2	20	Unbiased	1.2236	1.2235	-0.0001
3	50	Biased	1.2247	1.224	-0.0007
4	30	Unbiased	1.2222	1.2212	-0.001
5	50	Unbiased	1.2204	1.2198	-0.0006
6	30	Biased	1.2213	1.2207	-0.0006
7	50	Biased	1.222	1.2213	-0.0007
8	30	Unbiased	1.2212	1.2195	-0.0017
9	20	Unbiased	1.2205	1.2202	-0.0003
10	50	Biased	1.22	1.2195	-0.0005
11	30	Biased	1.2216	1.2214	-0.0002
12	0	Correlation	1.2237	1.223	-0.0007
13	0	Correlation	1.2254	1.2247	-0.0007
14	50	Unbiased	1.2204	1.2198	-0.0006
15	20	Biased	1.2203	1.2202	-0.0001
16	20	Unbiased	1.225	1.2242	-0.0008
17	20	Biased	1.2217	1.2209	-0.0008
18	20	Unbiased	1.2244	1.2231	-0.0013
19	20	Biased	1.2215	1.2214	-0.0001
20	50	Unbiased	1.2251	1.2246	-0.0005
21	0	Correlation	1.2224	1.2216	-0.0008
22	50	Unbiased	1.2245	1.225	0.0005
23	0	Correlation	1.2232	1.223	-0.0002
24	20	Biased	1.2233	1.2225	-0.0008
26	50	Biased	1.2206	1.2208	0.0002
27	30	Unbiased	1.2213	1.2213	0
28	30	Biased	1.2246	1.2232	-0.0014
29	30	Unbiased	1.2238	1.223	-0.0008
30	20	Biased	1.218	1.2181	0.0001
31	30	Unbiased	1.221	1.2209	-0.0001
33	30	Biased	1.2235	1.2228	-0.0007
34	50	Unbiased	1.2227	1.223	0.0003
35	20	Unbiased	1.2253	1.2251	-0.0002
41	30	Biased	1.2206	1.222	0.0014

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2224	1.2237	1.2254	0.0012685	1.2216	1.2231	1.2247	0.0012685	-0.0008	-0.0006	-0.0002	0.0002708
20	1.218	1.2224	1.2253	0.002359	1.2181	1.2219	1.2251	0.0021436	-0.0013	-0.00044	0.0001	0.00045265
30	1.2206	1.2221	1.2246	0.0013707	1.2195	1.2216	1.2232	0.0011605	-0.0017	-0.00051	0.0014	0.00086596
50	1.22	1.2222	1.2251	0.0019515	1.2195	1.2219	1.225	0.0020859	-0.0007	-0.00032	0.0005	0.0004614

Device Test: 22.1 LEVEL|SLOPE_2/RSC_A/4.5/4.5/0/0/4.5/100kHz//@SC_RSC_A_100K





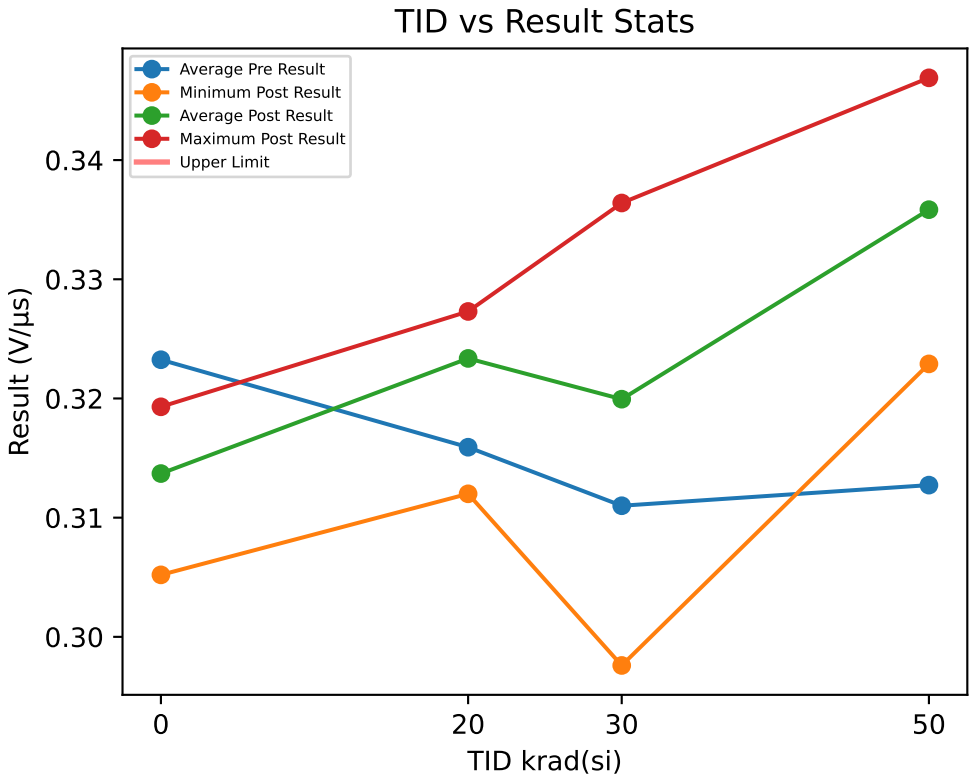
Test Results (No Limits Specified (V/µs))

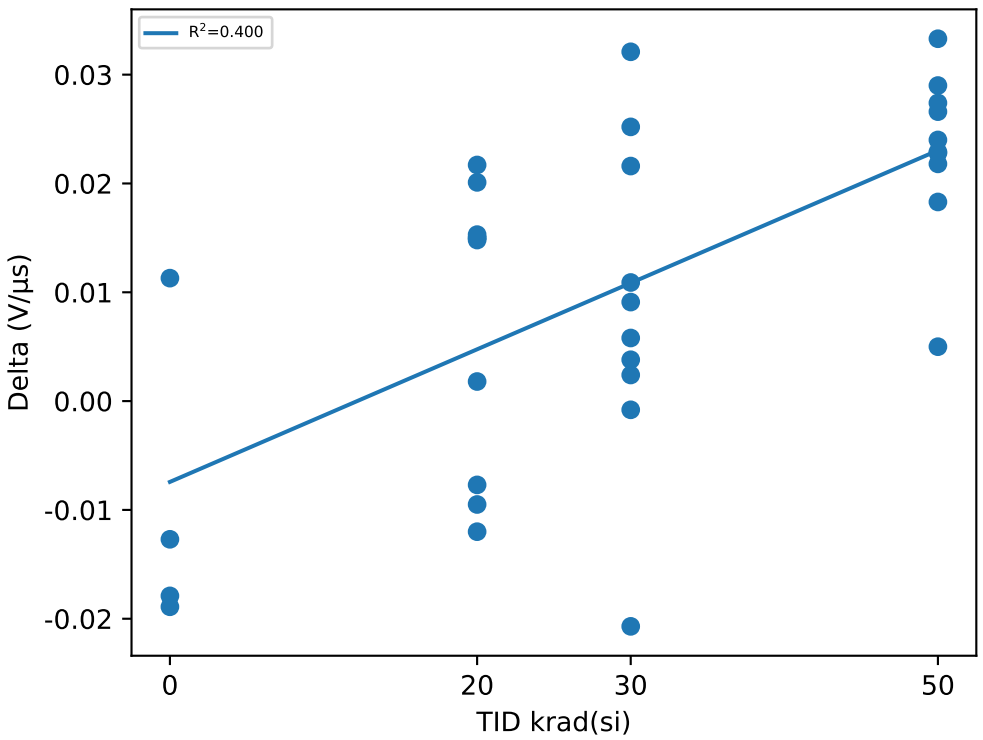
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	0.0289	0.0305	0.0016
2	20	Unbiased	0.028	0.0293	0.0013
3	50	Biased	0.028	0.0293	0.0013
4	30	Unbiased	0.0288	0.0294	0.0006
5	50	Unbiased	0.0283	0.0308	0.0025
6	30	Biased	0.0279	0.03	0.0021
7	50	Biased	0.0287	0.0301	0.0014
8	30	Unbiased	0.028	0.0285	0.0005
9	20	Unbiased	0.0289	0.0294	0.0005
10	50	Biased	0.0279	0.0292	0.0013
11	30	Biased	0.0279	0.0294	0.0015
12	0	Correlation	0.0285	0.0274	-0.0011
13	0	Correlation	0.0277	0.0266	-0.0011
14	50	Unbiased	0.0278	0.0297	0.0019
15	20	Biased	0.0273	0.0281	0.0008
16	20	Unbiased	0.0296	0.0294	-0.0002
17	20	Biased	0.0281	0.0286	0.0005
18	20	Unbiased	0.0279	0.0281	0.0002
19	20	Biased	0.0286	0.0298	0.0012
20	50	Unbiased	0.0291	0.0311	0.002
21	0	Correlation	0.0299	0.0291	-0.0008
22	50	Unbiased	0.0297	0.0313	0.0016
23	0	Correlation	0.0283	0.0278	-0.0005
24	20	Biased	0.0289	0.0288	-0.0001
26	50	Biased	0.0281	0.029	0.0009
27	30	Unbiased	0.0286	0.0305	0.0019
28	30	Biased	0.0275	0.0286	0.0011
29	30	Unbiased	0.0271	0.0271	0
30	20	Biased	0.028	0.0289	0.0009
31	30	Unbiased	0.0279	0.0277	-0.0002
33	30	Biased	0.0294	0.0308	0.0014
34	50	Unbiased	0.029	0.0307	0.0017
35	20	Unbiased	0.0286	0.0305	0.0019
41	30	Biased	0.0291	0.0297	0.0006

Test Statistics (V/µs)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.0277	0.0286	0.0299	0.00093095	0.0266	0.027725	0.0291	0.0010436	-0.0011	-0.000875	-0.0005	0.00028723
20	0.0273	0.02839	0.0296	0.00065735	0.0281	0.02909	0.0305	0.000749	-0.0002	0.0007	0.0019	0.00065659
30	0.0271	0.02822	0.0294	0.00072847	0.0271	0.02917	0.0308	0.0011889	-0.0002	0.00095	0.0021	0.00077639
50	0.0278	0.02855	0.0297	0.00062583	0.029	0.03017	0.0313	0.0008314	0.0009	0.00162	0.0025	0.00044422

Device Test: 22.10 LEVEL|SLOPE_2/RSC_C/5/5/0/0/5/500kHz//@SC_RSC_C_500K





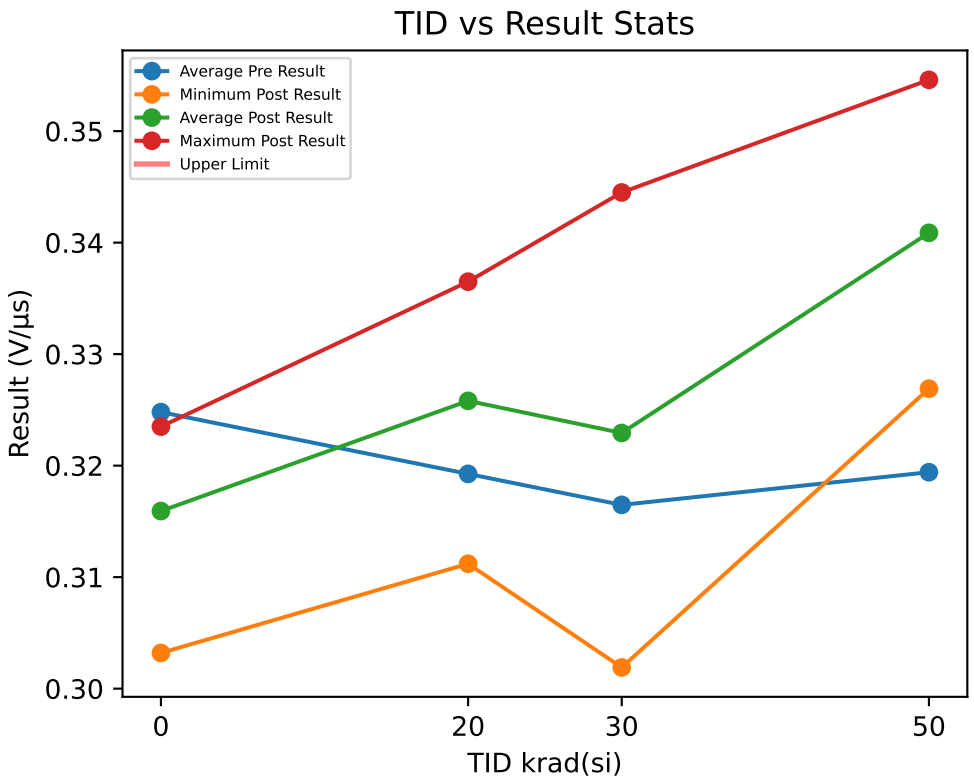
Test Results (No Limits Specified (V/µs))

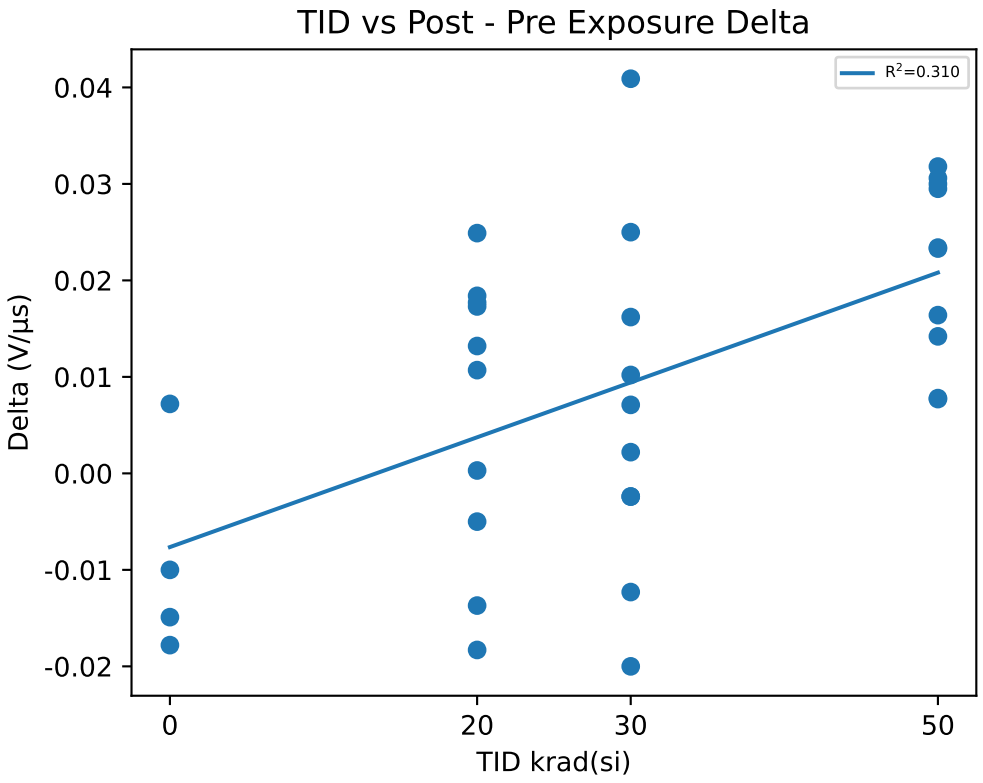
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	0.3347	0.3397	0.005
2	20	Unbiased	0.3103	0.3256	0.0153
3	50	Biased	0.2994	0.3327	0.0333
4	30	Unbiased	0.3089	0.3113	0.0024
5	50	Unbiased	0.3215	0.3398	0.0183
6	30	Biased	0.3034	0.3286	0.0252
7	50	Biased	0.3054	0.3344	0.029
8	30	Unbiased	0.3211	0.3203	-0.0008
9	20	Unbiased	0.3347	0.3227	-0.012
10	50	Biased	0.3041	0.3307	0.0266
11	30	Biased	0.3017	0.3338	0.0321
12	0	Correlation	0.3299	0.3172	-0.0127
13	0	Correlation	0.332	0.3131	-0.0189
14	50	Unbiased	0.3005	0.3245	0.024
15	20	Biased	0.2997	0.3214	0.0217
16	20	Unbiased	0.3353	0.3258	-0.0095
17	20	Biased	0.3197	0.312	-0.0077
18	20	Unbiased	0.3123	0.3273	0.015
19	20	Biased	0.3112	0.3262	0.015
20	50	Unbiased	0.3195	0.3469	0.0274
21	0	Correlation	0.3372	0.3193	-0.0179
22	50	Unbiased	0.3204	0.3422	0.0218
23	0	Correlation	0.2939	0.3052	0.0113
24	20	Biased	0.3183	0.3201	0.0018
26	50	Biased	0.3	0.3229	0.0229
27	30	Unbiased	0.3052	0.3268	0.0216
28	30	Biased	0.3161	0.3252	0.0091
29	30	Unbiased	0.3094	0.3152	0.0058
30	20	Biased	0.3111	0.3259	0.0148
31	30	Unbiased	0.2933	0.3042	0.0109
33	30	Biased	0.3326	0.3364	0.0038
34	50	Unbiased	0.3218	0.3446	0.0228
35	20	Unbiased	0.3065	0.3266	0.0201
41	30	Biased	0.3183	0.2976	-0.0207

Test Statistics (V/µs)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.2939	0.32325	0.3372	0.019806	0.3052	0.3137	0.3193	0.0062241	-0.0189	-0.00955	0.0113	0.014163
20	0.2997	0.31591	0.3353	0.0115	0.312	0.32336	0.3273	0.0046603	-0.012	0.00745	0.0217	0.012995
30	0.2933	0.311	0.3326	0.011284	0.2976	0.31994	0.3364	0.012723	-0.0207	0.00894	0.0321	0.014972
50	0.2994	0.31273	0.3347	0.012311	0.3229	0.33584	0.3469	0.0081954	0.005	0.02311	0.0333	0.0076221

Device Test: 22.11 LEVEL|SLOPE_2/RSC_C/12/12/0/0/5/500kHz//@SC_RSC_C_500K





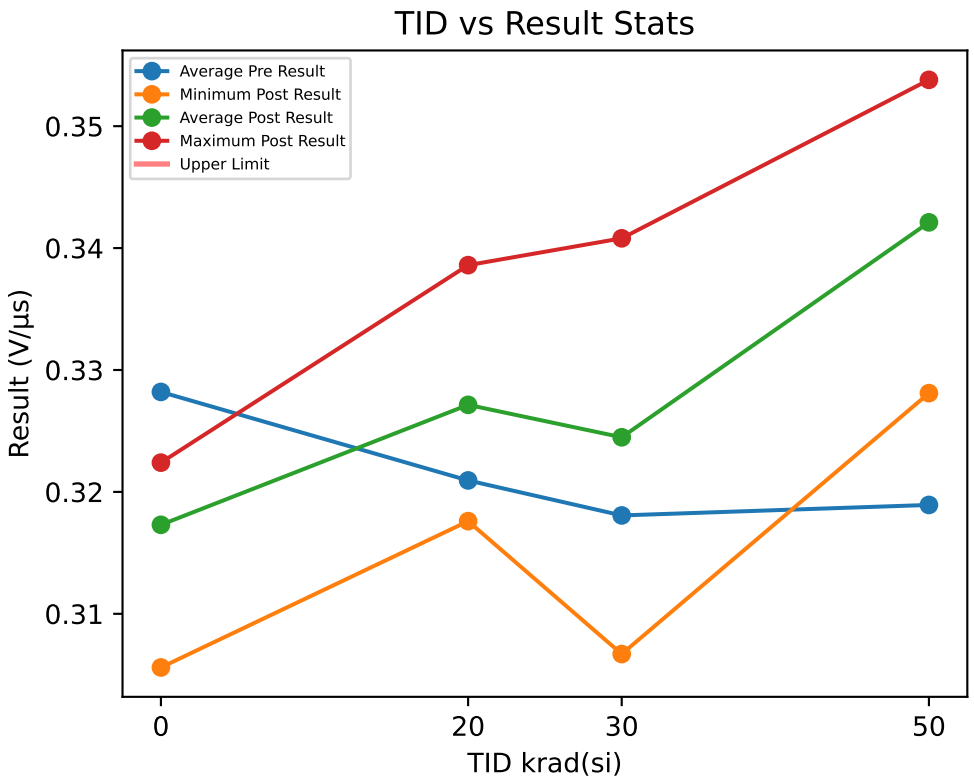
Test Results (No Limits Specified (V/µs))

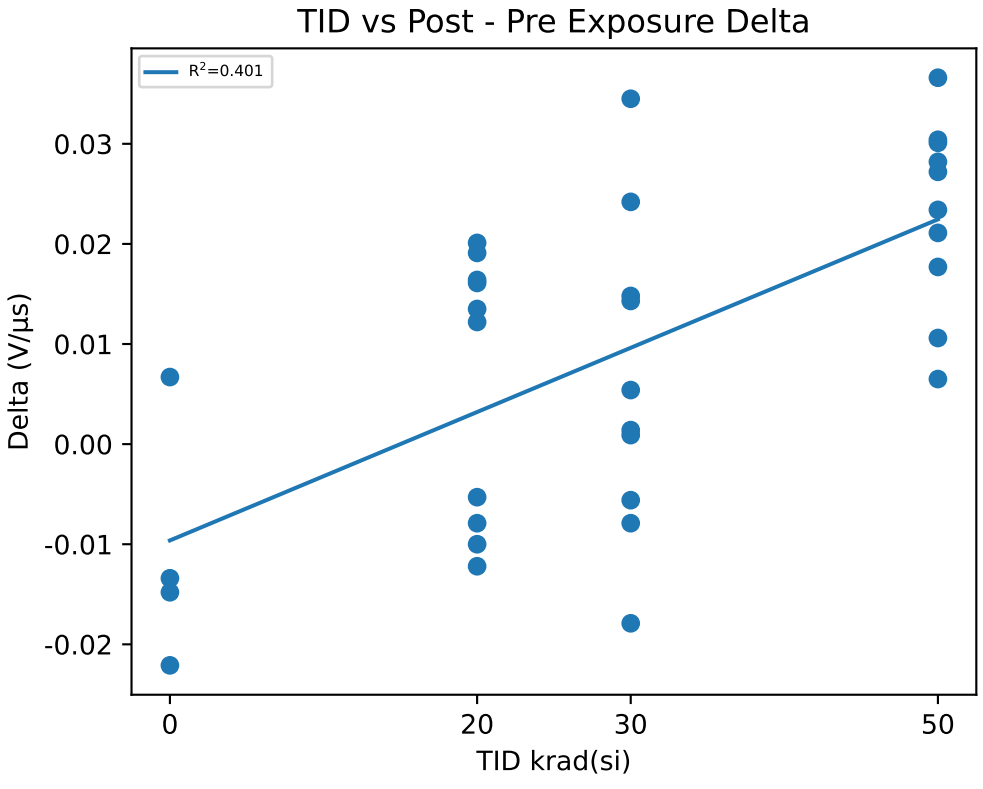
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	0.3393	0.3471	0.0078
2	20	Unbiased	0.3114	0.3221	0.0107
3	50	Biased	0.3104	0.3399	0.0295
4	30	Unbiased	0.319	0.3166	-0.0024
5	50	Unbiased	0.3333	0.341	0.0077
6	30	Biased	0.3128	0.3378	0.025
7	50	Biased	0.3142	0.3375	0.0233
8	30	Unbiased	0.331	0.3187	-0.0123
9	20	Unbiased	0.3324	0.3274	-0.005
10	50	Biased	0.3028	0.3346	0.0318
11	30	Biased	0.3002	0.3411	0.0409
12	0	Correlation	0.3324	0.3224	-0.01
13	0	Correlation	0.3295	0.3146	-0.0149
14	50	Unbiased	0.3078	0.3312	0.0234
15	20	Biased	0.3026	0.3203	0.0177
16	20	Unbiased	0.3381	0.3244	-0.0137
17	20	Biased	0.3295	0.3112	-0.0183
18	20	Unbiased	0.3117	0.3249	0.0132
19	20	Biased	0.3116	0.3365	0.0249
20	50	Unbiased	0.3321	0.3463	0.0142
21	0	Correlation	0.3413	0.3235	-0.0178
22	50	Unbiased	0.3246	0.3546	0.03
23	0	Correlation	0.296	0.3032	0.0072
24	20	Biased	0.3245	0.3248	0.0003
26	50	Biased	0.3105	0.3269	0.0164
27	30	Unbiased	0.3053	0.3215	0.0162
28	30	Biased	0.3165	0.3267	0.0102
29	30	Unbiased	0.319	0.3166	-0.0024
30	20	Biased	0.3127	0.3311	0.0184
31	30	Unbiased	0.3017	0.3039	0.0022
33	30	Biased	0.3374	0.3445	0.0071
34	50	Unbiased	0.3191	0.3497	0.0306
35	20	Unbiased	0.3181	0.3354	0.0173
41	30	Biased	0.3219	0.3019	-0.02

Test Statistics (V/µs)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.296	0.3248	0.3413	0.019846	0.3032	0.31593	0.3235	0.0093628	-0.0178	-0.008875	0.0072	0.01119
20	0.3026	0.31926	0.3381	0.01135	0.3112	0.32581	0.3365	0.0074399	-0.0183	0.00655	0.0249	0.014827
30	0.3002	0.31648	0.3374	0.012076	0.3019	0.32293	0.3445	0.014664	-0.02	0.00645	0.0409	0.017846
50	0.3028	0.31941	0.3393	0.01236	0.3269	0.34088	0.3546	0.0086607	0.0077	0.02147	0.0318	0.0093655

Device Test: 22.12 LEVEL|SLOPE_2/RSC_C/14/14/0/0/5/500kHz//@SC_RSC_C_500K





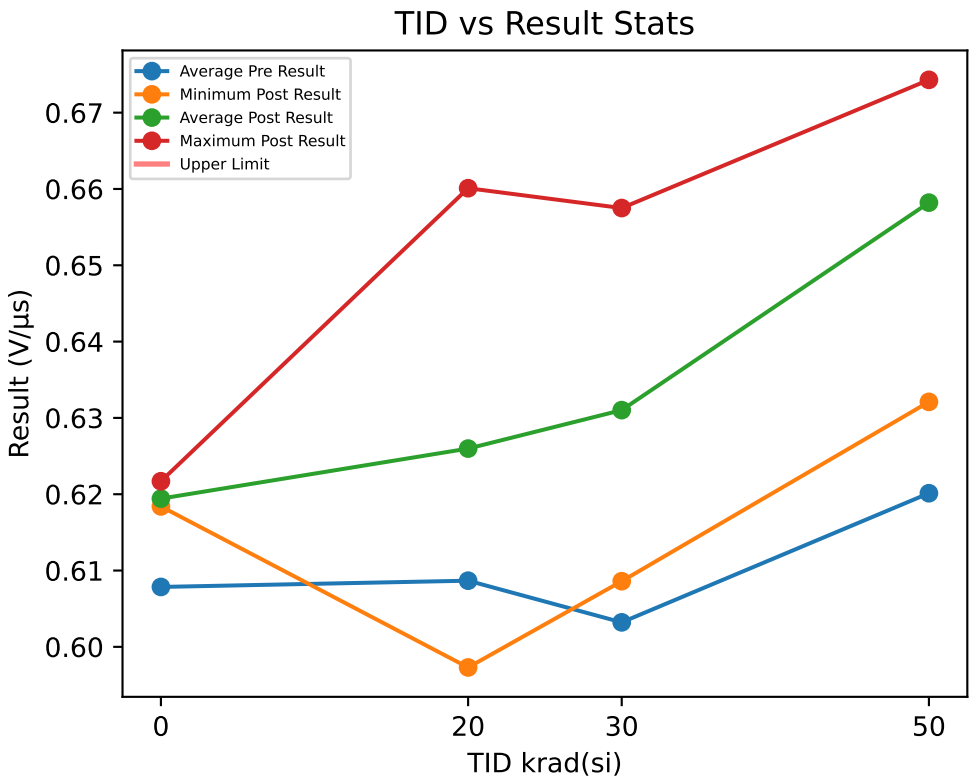
Test Results (No Limits Specified (V/µs))

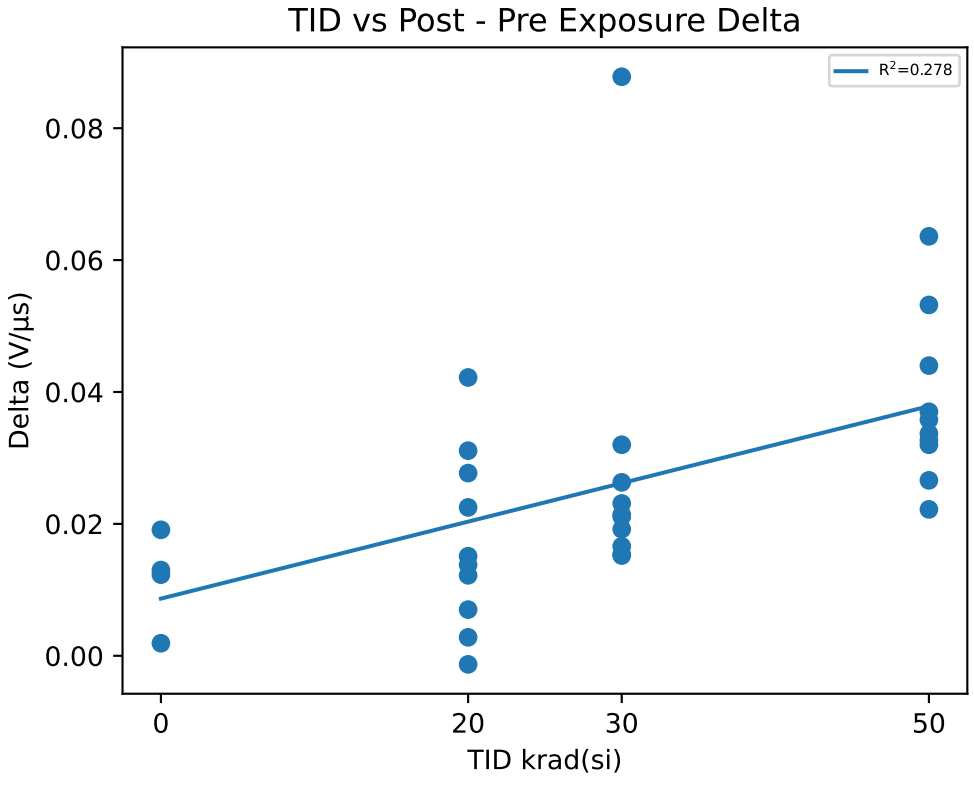
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	0.3425	0.3531	0.0106
2	20	Unbiased	0.3109	0.3273	0.0164
3	50	Biased	0.3132	0.3414	0.0282
4	30	Unbiased	0.3181	0.319	0.0009
5	50	Unbiased	0.3374	0.3439	0.0065
6	30	Biased	0.3087	0.3329	0.0242
7	50	Biased	0.3066	0.3367	0.0301
8	30	Unbiased	0.327	0.3214	-0.0056
9	20	Unbiased	0.3375	0.3296	-0.0079
10	50	Biased	0.3038	0.3342	0.0304
11	30	Biased	0.3049	0.3394	0.0345
12	0	Correlation	0.3372	0.3224	-0.0148
13	0	Correlation	0.3324	0.319	-0.0134
14	50	Unbiased	0.307	0.3281	0.0211
15	20	Biased	0.3014	0.3215	0.0201
16	20	Unbiased	0.3386	0.3264	-0.0122
17	20	Biased	0.3276	0.3176	-0.01
18	20	Unbiased	0.3145	0.328	0.0135
19	20	Biased	0.3151	0.3342	0.0191
20	50	Unbiased	0.3319	0.3496	0.0177
21	0	Correlation	0.3443	0.3222	-0.0221
22	50	Unbiased	0.3172	0.3538	0.0366
23	0	Correlation	0.2989	0.3056	0.0067
24	20	Biased	0.3255	0.3202	-0.0053
26	50	Biased	0.3062	0.3334	0.0272
27	30	Unbiased	0.3122	0.327	0.0148
28	30	Biased	0.316	0.3303	0.0143
29	30	Unbiased	0.3264	0.3185	-0.0079
30	20	Biased	0.3158	0.328	0.0122
31	30	Unbiased	0.3034	0.3088	0.0054
33	30	Biased	0.3394	0.3408	0.0014
34	50	Unbiased	0.3235	0.3469	0.0234
35	20	Unbiased	0.3225	0.3386	0.0161
41	30	Biased	0.3246	0.3067	-0.0179

Test Statistics (V/µs)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.2989	0.3282	0.3443	0.020136	0.3056	0.3173	0.3224	0.007954	-0.0221	-0.0109	0.0067	0.012338
20	0.3014	0.32094	0.3386	0.01173	0.3176	0.32714	0.3386	0.0063269	-0.0122	0.0062	0.0201	0.013262
30	0.3034	0.31807	0.3394	0.011362	0.3067	0.32448	0.3408	0.011725	-0.0179	0.00641	0.0345	0.015757
50	0.3038	0.31893	0.3425	0.014169	0.3281	0.34211	0.3538	0.0088454	0.0065	0.02318	0.0366	0.0093829

Device Test: 22.13 LEVEL|SLOPE_2/RSC_D/4.5/4.5/0/0/4.5/1MHz//@SC_RSC_D_1M





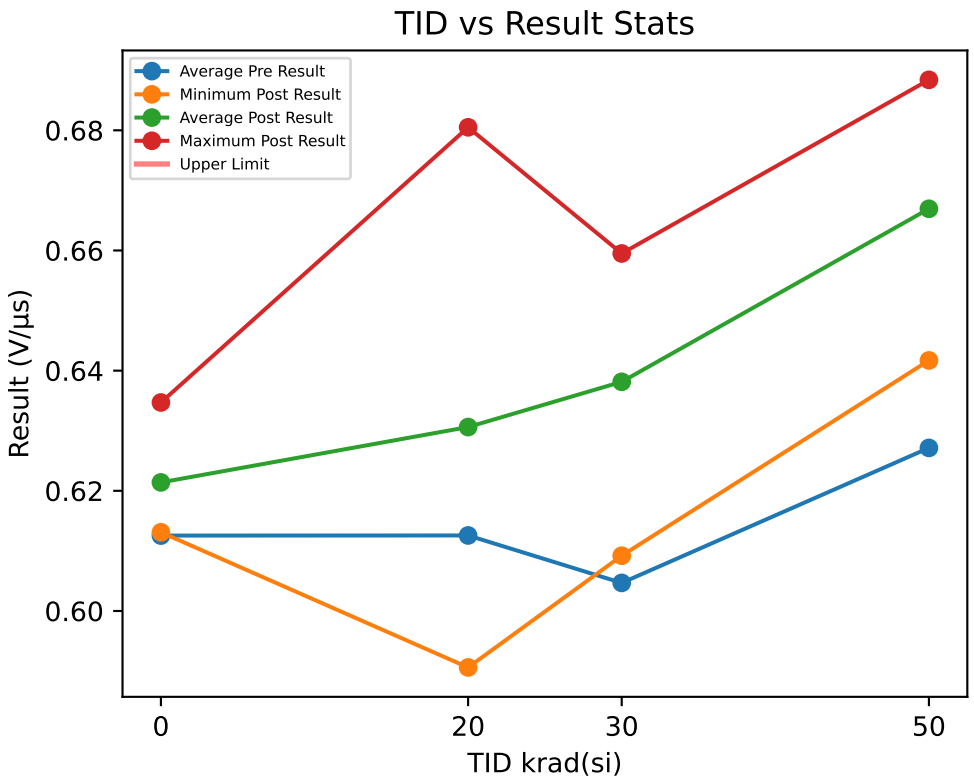
Test Results (No Limits Specified (V/µs))

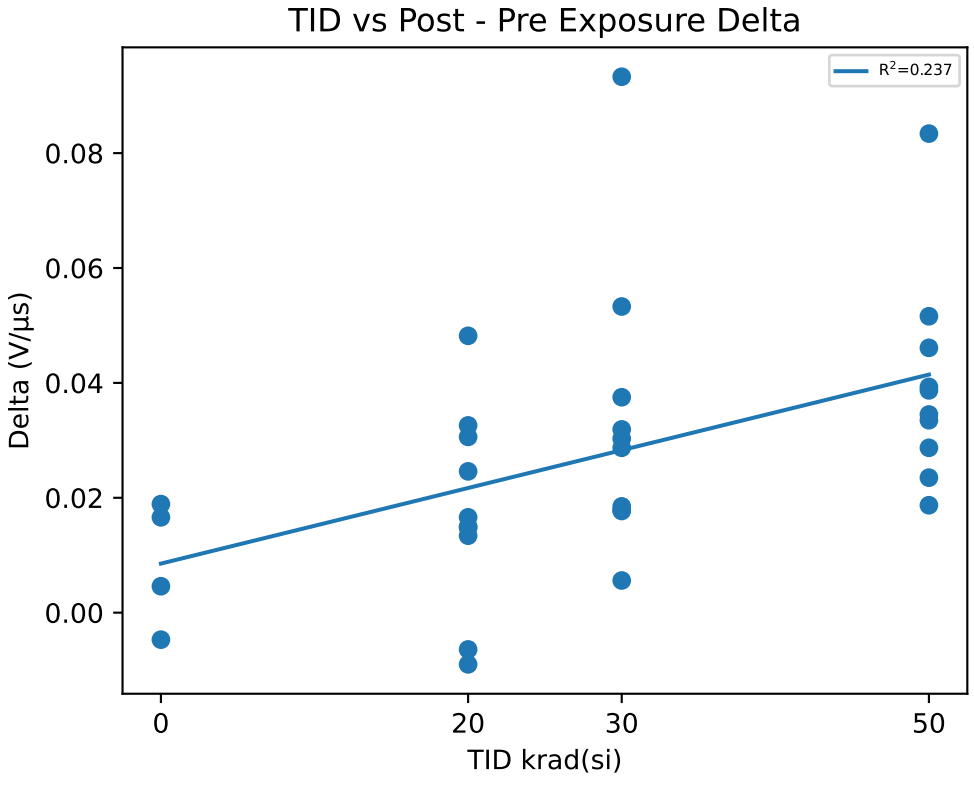
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	0.6252	0.6692	0.044
2	20	Unbiased	0.5868	0.6093	0.0225
3	50	Biased	0.6381	0.6708	0.0327
4	30	Unbiased	0.5982	0.6148	0.0166
5	50	Unbiased	0.6087	0.6407	0.032
6	30	Biased	0.6135	0.6346	0.0211
7	50	Biased	0.6291	0.6628	0.0337
8	30	Unbiased	0.6228	0.6442	0.0214
9	20	Unbiased	0.5945	0.5973	0.0028
10	50	Biased	0.6181	0.6403	0.0222
11	30	Biased	0.6186	0.6378	0.0192
12	0	Correlation	0.5995	0.6186	0.0191
13	0	Correlation	0.6171	0.619	0.0019
14	50	Unbiased	0.6265	0.6531	0.0266
15	20	Biased	0.618	0.625	0.007
16	20	Unbiased	0.6011	0.6288	0.0277
17	20	Biased	0.5906	0.6217	0.0311
18	20	Unbiased	0.6166	0.6317	0.0151
19	20	Biased	0.6479	0.6601	0.0122
20	50	Unbiased	0.6151	0.6683	0.0532
21	0	Correlation	0.6094	0.6217	0.0123
22	50	Unbiased	0.6335	0.6705	0.037
23	0	Correlation	0.6054	0.6184	0.013
24	20	Biased	0.6052	0.6474	0.0422
26	50	Biased	0.5963	0.6321	0.0358
27	30	Unbiased	0.5932	0.6086	0.0154
28	30	Biased	0.6053	0.6373	0.032
29	30	Unbiased	0.5913	0.6144	0.0231
30	20	Biased	0.618	0.6318	0.0138
31	30	Unbiased	0.606	0.6212	0.0152
33	30	Biased	0.6135	0.6398	0.0263
34	50	Unbiased	0.6107	0.6743	0.0636
35	20	Unbiased	0.608	0.6067	-0.0013
41	30	Biased	0.5697	0.6575	0.0878

Test Statistics (V/µs)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.5995	0.60785	0.6171	0.0073867	0.6184	0.61943	0.6217	0.001537	0.0019	0.011575	0.0191	0.0071365
20	0.5868	0.60867	0.6479	0.017799	0.5973	0.62598	0.6601	0.018825	-0.0013	0.01731	0.0422	0.013544
30	0.5697	0.60321	0.6228	0.015757	0.6086	0.63102	0.6575	0.015594	0.0152	0.02781	0.0878	0.021704
50	0.5963	0.62013	0.6381	0.01276	0.6321	0.65821	0.6743	0.015446	0.0222	0.03808	0.0636	0.012429

Device Test: 22.14 LEVEL|SLOPE_2/RSC_D/5/5/0/0/5/1MHz//@SC_RSC_D_1M





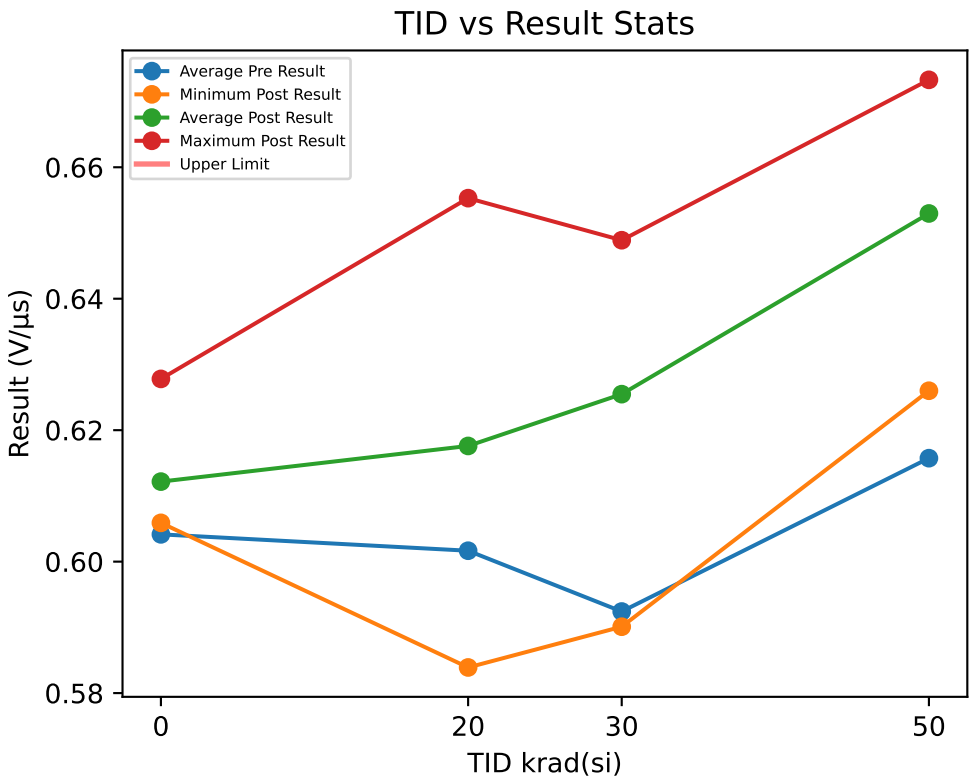
Test Results (No Limits Specified (V/µs))

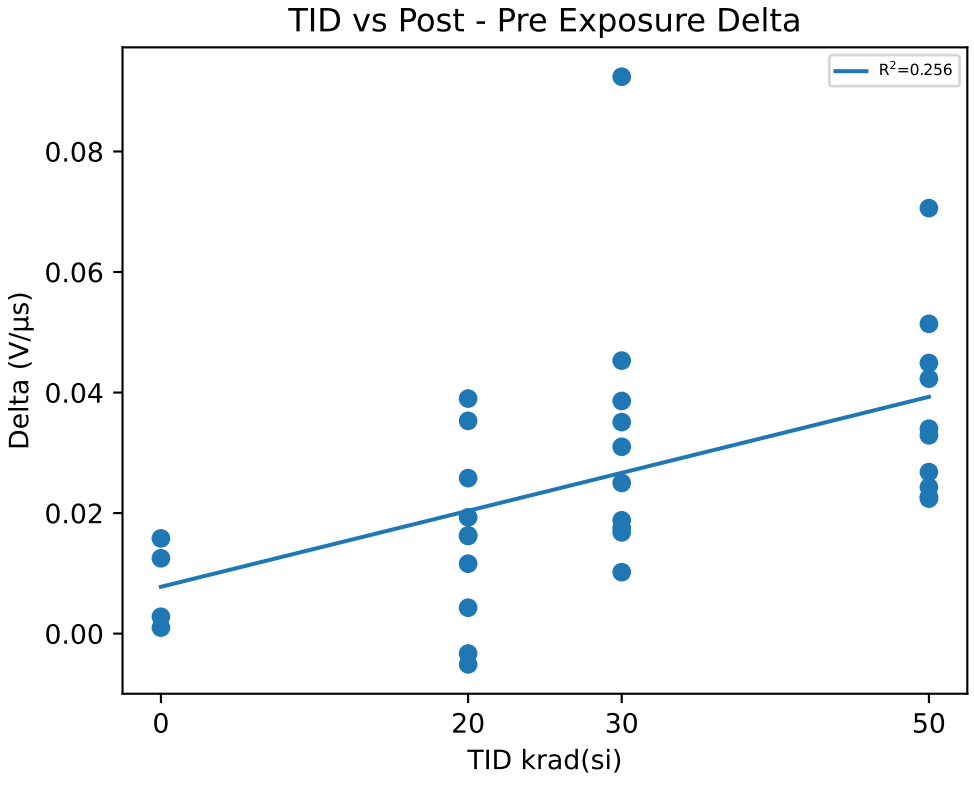
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	0.6424	0.6811	0.0387
2	20	Unbiased	0.5834	0.5984	0.015
3	50	Biased	0.6417	0.6652	0.0235
4	30	Unbiased	0.5998	0.6301	0.0303
5	50	Unbiased	0.6092	0.6485	0.0393
6	30	Biased	0.6293	0.647	0.0177
7	50	Biased	0.6361	0.6648	0.0287
8	30	Unbiased	0.6232	0.6551	0.0319
9	20	Unbiased	0.597	0.5906	-0.0064
10	50	Biased	0.6236	0.6571	0.0335
11	30	Biased	0.6195	0.6374	0.0179
12	0	Correlation	0.6085	0.6131	0.0046
13	0	Correlation	0.6158	0.6347	0.0189
14	50	Unbiased	0.6375	0.6562	0.0187
15	20	Biased	0.6211	0.6359	0.0148
16	20	Unbiased	0.5936	0.6242	0.0306
17	20	Biased	0.6011	0.6257	0.0246
18	20	Unbiased	0.6259	0.6393	0.0134
19	20	Biased	0.6479	0.6805	0.0326
20	50	Unbiased	0.6328	0.6844	0.0516
21	0	Correlation	0.6063	0.6229	0.0166
22	50	Unbiased	0.6359	0.682	0.0461
23	0	Correlation	0.6196	0.6149	-0.0047
24	20	Biased	0.608	0.6562	0.0482
26	50	Biased	0.6072	0.6417	0.0345
27	30	Unbiased	0.5907	0.6092	0.0185
28	30	Biased	0.6002	0.6535	0.0533
29	30	Unbiased	0.5938	0.6225	0.0287
30	20	Biased	0.6252	0.6418	0.0166
31	30	Unbiased	0.6096	0.6152	0.0056
33	30	Biased	0.6144	0.6519	0.0375
34	50	Unbiased	0.605	0.6884	0.0834
35	20	Unbiased	0.6225	0.6135	-0.009
41	30	Biased	0.5662	0.6595	0.0933

Test Statistics (V/µs)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.6063	0.61255	0.6196	0.006211	0.6131	0.6214	0.6347	0.0098367	-0.0047	0.00885	0.0189	0.010996
20	0.5834	0.61257	0.6479	0.019329	0.5906	0.63061	0.6805	0.026602	-0.009	0.01804	0.0482	0.017302
30	0.5662	0.60467	0.6293	0.018636	0.6092	0.63814	0.6595	0.018016	0.0056	0.03347	0.0933	0.024757
50	0.605	0.62714	0.6424	0.01477	0.6417	0.66694	0.6884	0.016294	0.0187	0.0398	0.0834	0.018206

Device Test: 22.15 LEVEL|SLOPE_2/RSC_D/12/12/0/0/5/1MHz//@SC_RSC_D_1M





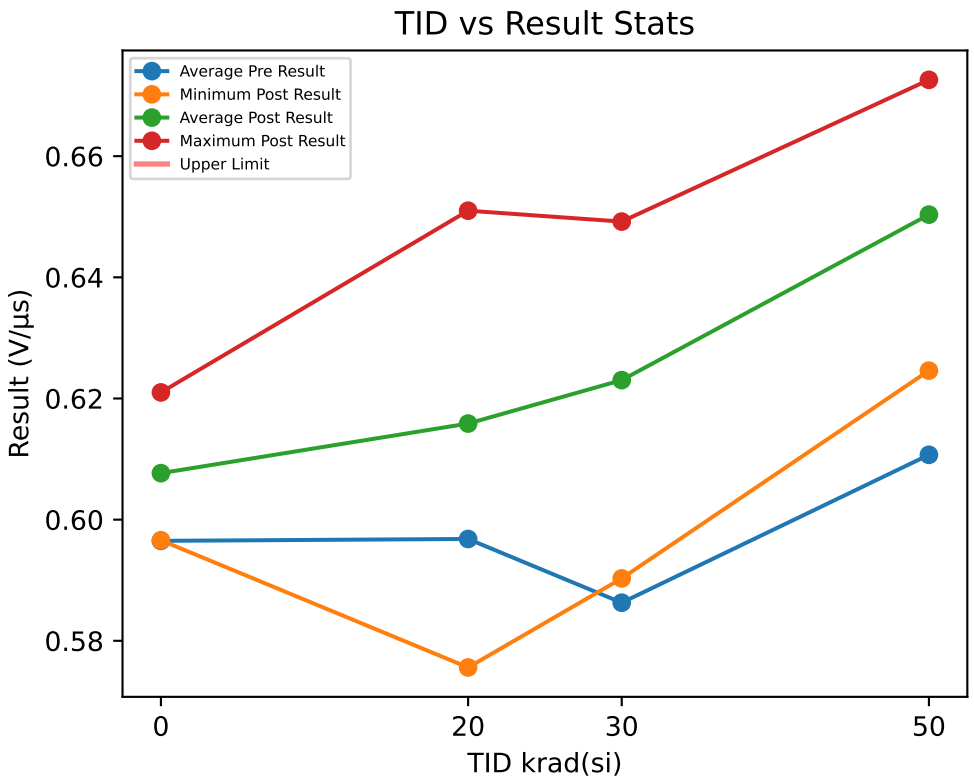
Test Results (No Limits Specified (V/µs))

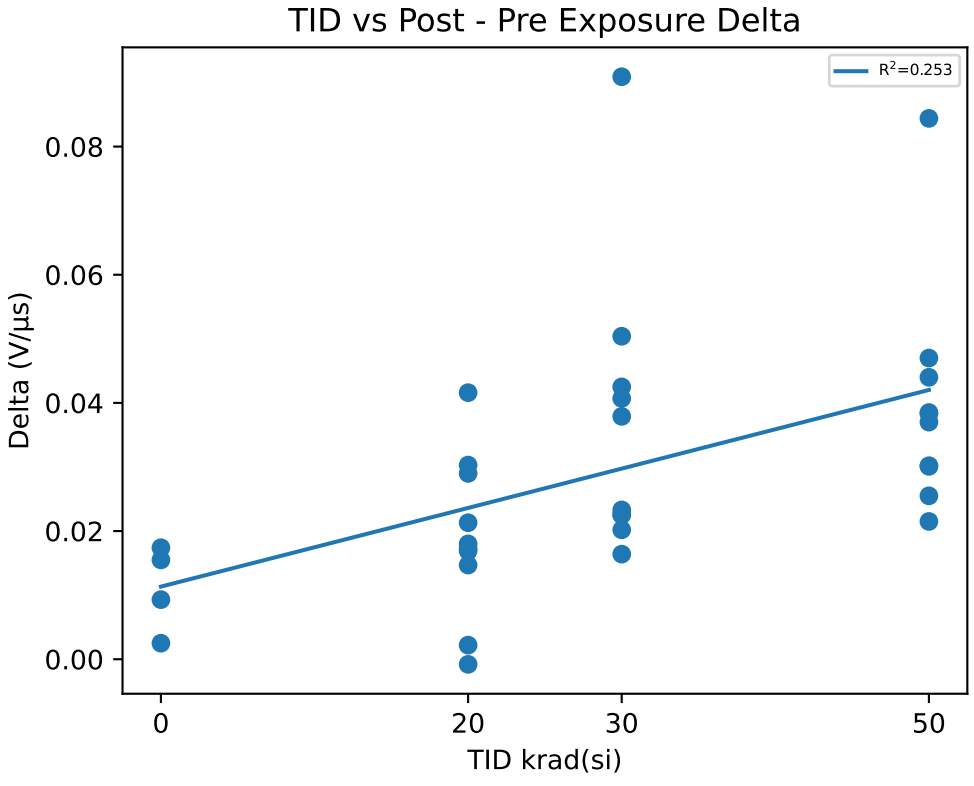
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	0.6302	0.6725	0.0423
2	20	Unbiased	0.5779	0.5895	0.0116
3	50	Biased	0.6285	0.6553	0.0268
4	30	Unbiased	0.5788	0.5976	0.0188
5	50	Unbiased	0.6021	0.635	0.0329
6	30	Biased	0.6166	0.6416	0.025
7	50	Biased	0.6203	0.6446	0.0243
8	30	Unbiased	0.6079	0.6465	0.0386
9	20	Unbiased	0.5872	0.5839	-0.0033
10	50	Biased	0.6124	0.6464	0.034
11	30	Biased	0.6052	0.6227	0.0175
12	0	Correlation	0.6031	0.6059	0.0028
13	0	Correlation	0.612	0.6278	0.0158
14	50	Unbiased	0.6209	0.6433	0.0224
15	20	Biased	0.6107	0.627	0.0163
16	20	Unbiased	0.5785	0.6138	0.0353
17	20	Biased	0.5826	0.6084	0.0258
18	20	Unbiased	0.6185	0.6228	0.0043
19	20	Biased	0.636	0.6553	0.0193
20	50	Unbiased	0.6223	0.6672	0.0449
21	0	Correlation	0.5943	0.6068	0.0125
22	50	Unbiased	0.6219	0.6733	0.0514
23	0	Correlation	0.6072	0.6082	0.001
24	20	Biased	0.6031	0.6421	0.039
26	50	Biased	0.6033	0.626	0.0227
27	30	Unbiased	0.5733	0.5901	0.0168
28	30	Biased	0.596	0.6413	0.0453
29	30	Unbiased	0.5856	0.6207	0.0351
30	20	Biased	0.6181	0.6343	0.0162
31	30	Unbiased	0.5914	0.6016	0.0102
33	30	Biased	0.6128	0.6438	0.031
34	50	Unbiased	0.5955	0.6661	0.0706
35	20	Unbiased	0.604	0.5989	-0.0051
41	30	Biased	0.5565	0.6489	0.0924

Test Statistics (V/µs)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.5943	0.60415	0.612	0.0075067	0.6059	0.61218	0.6278	0.01046	0.001	0.008025	0.0158	0.0072371
20	0.5779	0.60166	0.636	0.019708	0.5839	0.6176	0.6553	0.02307	-0.0051	0.01594	0.039	0.014842
30	0.5565	0.59241	0.6166	0.019162	0.5901	0.62548	0.6489	0.022276	0.0102	0.03307	0.0924	0.023588
50	0.5955	0.61574	0.6302	0.011841	0.626	0.65297	0.6733	0.016439	0.0224	0.03723	0.0706	0.015402

Device Test: 22.16 LEVEL|SLOPE_2/RSC_D/14/14/0/0/5/1MHz//@SC_RSC_D_1M





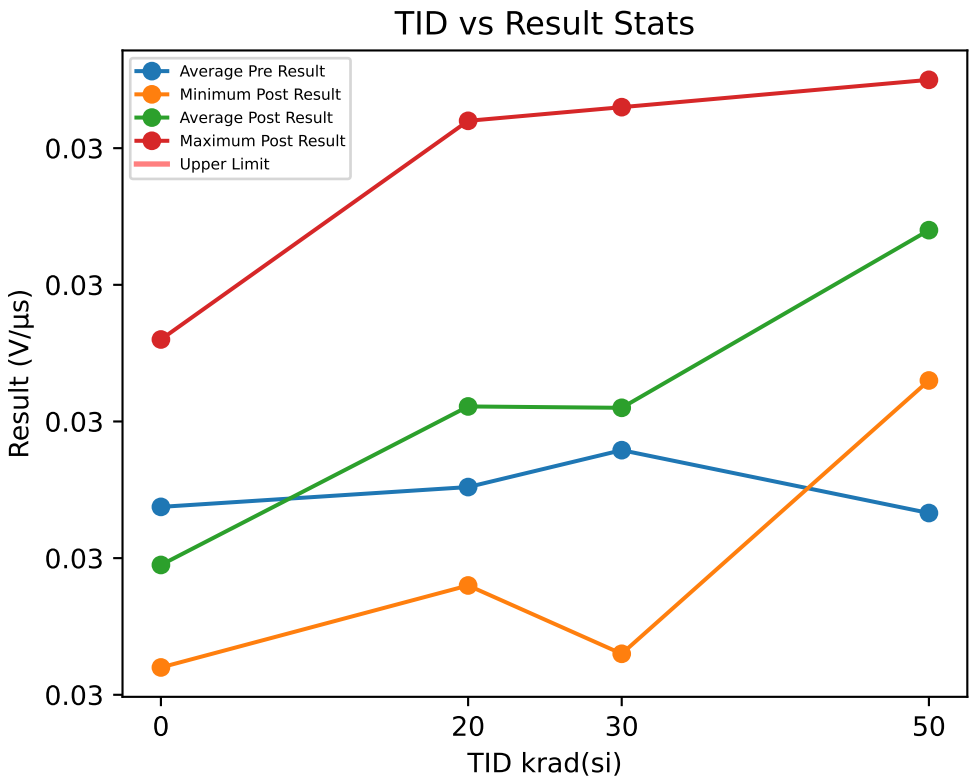
Test Results (No Limits Specified (V/µs))

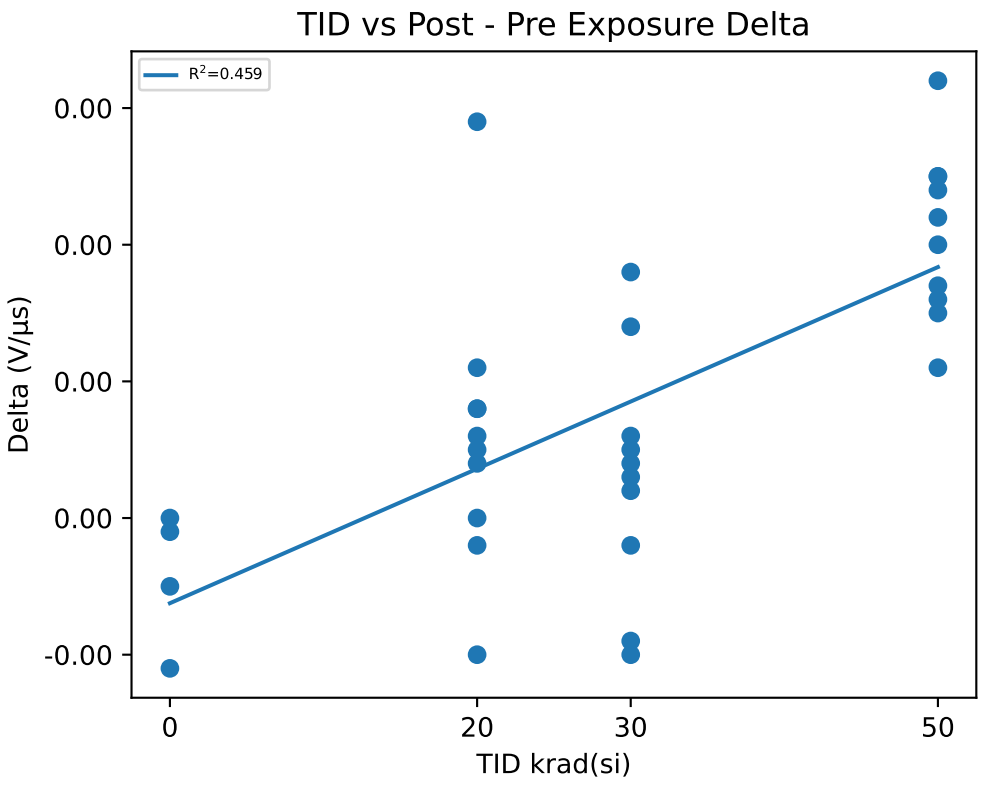
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	0.6241	0.6681	0.044
2	20	Unbiased	0.5732	0.5879	0.0147
3	50	Biased	0.629	0.6545	0.0255
4	30	Unbiased	0.5788	0.6013	0.0225
5	50	Unbiased	0.597	0.6353	0.0383
6	30	Biased	0.5949	0.6328	0.0379
7	50	Biased	0.6097	0.6398	0.0301
8	30	Unbiased	0.604	0.6465	0.0425
9	20	Unbiased	0.5764	0.5756	-0.0008
10	50	Biased	0.6039	0.6424	0.0385
11	30	Biased	0.5956	0.6189	0.0233
12	0	Correlation	0.5941	0.5966	0.0025
13	0	Correlation	0.6036	0.621	0.0174
14	50	Unbiased	0.62	0.6415	0.0215
15	20	Biased	0.6074	0.6243	0.0169
16	20	Unbiased	0.5777	0.608	0.0303
17	20	Biased	0.5841	0.6131	0.029
18	20	Unbiased	0.6108	0.6288	0.018
19	20	Biased	0.6337	0.651	0.0173
20	50	Unbiased	0.6185	0.6555	0.037
21	0	Correlation	0.5927	0.602	0.0093
22	50	Unbiased	0.6256	0.6726	0.047
23	0	Correlation	0.5956	0.6111	0.0155
24	20	Biased	0.5986	0.6402	0.0416
26	50	Biased	0.5944	0.6246	0.0302
27	30	Unbiased	0.5677	0.5903	0.0226
28	30	Biased	0.5905	0.6409	0.0504
29	30	Unbiased	0.5886	0.6088	0.0202
30	20	Biased	0.6094	0.6307	0.0213
31	30	Unbiased	0.5833	0.5997	0.0164
33	30	Biased	0.6085	0.6492	0.0407
34	50	Unbiased	0.5848	0.6692	0.0844
35	20	Unbiased	0.5968	0.599	0.0022
41	30	Biased	0.551	0.6419	0.0909

Test Statistics (V/µs)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.5927	0.5965	0.6036	0.0048792	0.5966	0.60767	0.621	0.010711	0.0025	0.011175	0.0174	0.0067386
20	0.5732	0.59681	0.6337	0.019239	0.5756	0.61586	0.651	0.02367	-0.0008	0.01905	0.0416	0.01267
30	0.551	0.58629	0.6085	0.017149	0.5903	0.62303	0.6492	0.021893	0.0164	0.03674	0.0909	0.022213
50	0.5848	0.6107	0.629	0.015112	0.6246	0.65035	0.6726	0.016164	0.0215	0.03965	0.0844	0.017625

Device Test: 22.2 LEVEL|SLOPE_2/RSC_A/5/5/0/0/5/100kHz//@SC_RSC_A_100K





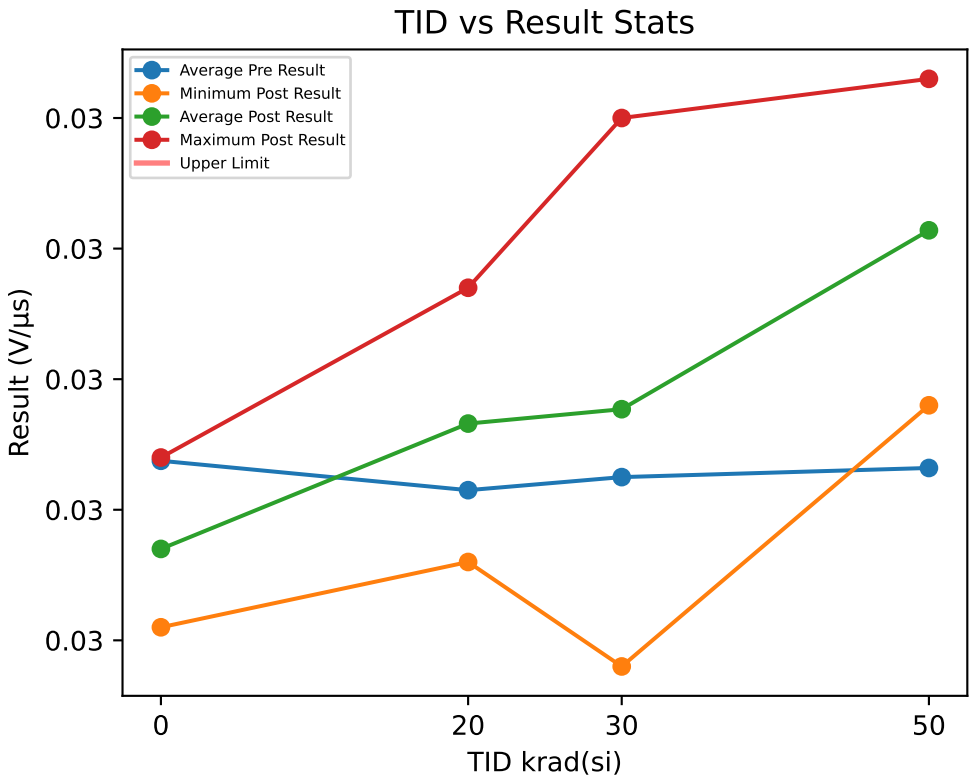
Test Results (No Limits Specified (V/µs))

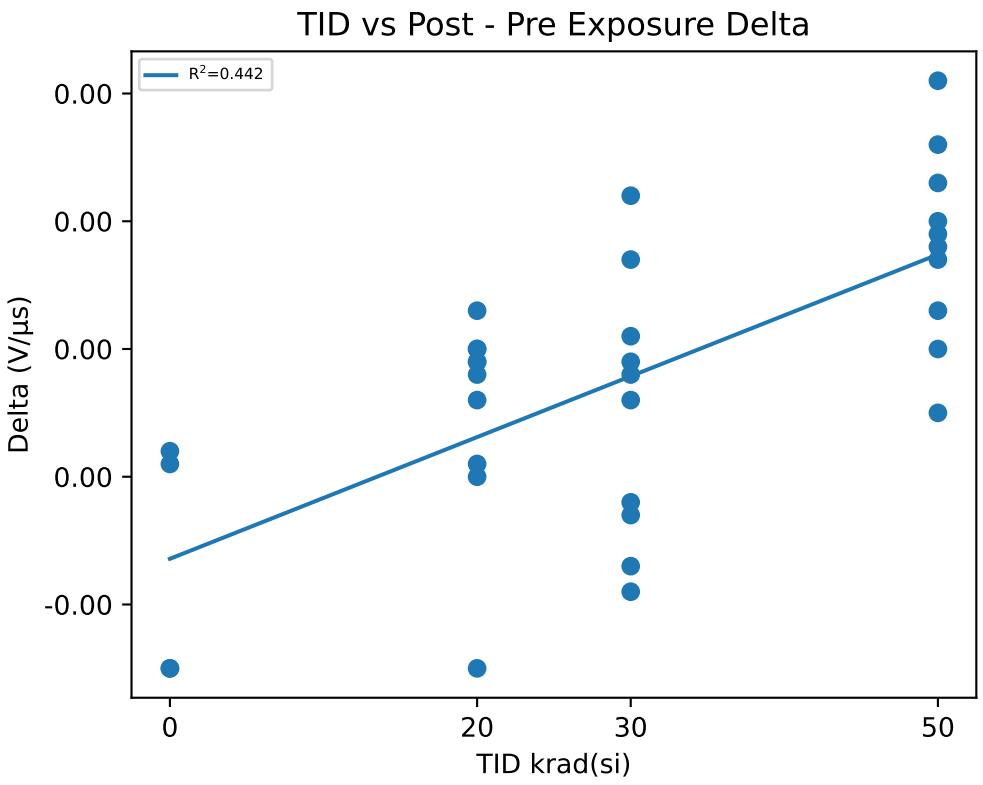
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	0.0293	0.0304	0.0011
2	20	Unbiased	0.0281	0.0289	0.0008
3	50	Biased	0.0281	0.0296	0.0015
4	30	Unbiased	0.0289	0.0291	0.0002
5	50	Unbiased	0.0283	0.0307	0.0024
6	30	Biased	0.0293	0.0291	-0.0002
7	50	Biased	0.0289	0.0306	0.0017
8	30	Unbiased	0.0292	0.0283	-0.0009
9	20	Unbiased	0.029	0.0296	0.0006
10	50	Biased	0.0272	0.0297	0.0025
11	30	Biased	0.0277	0.0295	0.0018
12	0	Correlation	0.0278	0.0277	-0.0001
13	0	Correlation	0.0272	0.0272	0
14	50	Unbiased	0.0268	0.03	0.0032
15	20	Biased	0.0272	0.028	0.0008
16	20	Unbiased	0.0299	0.0289	-0.001
17	20	Biased	0.0278	0.0278	0
18	20	Unbiased	0.0277	0.0288	0.0011
19	20	Biased	0.0294	0.0298	0.0004
20	50	Unbiased	0.0286	0.0311	0.0025
21	0	Correlation	0.0301	0.0296	-0.0005
22	50	Unbiased	0.0295	0.0315	0.002
23	0	Correlation	0.0284	0.0273	-0.0011
24	20	Biased	0.029	0.0288	-0.0002
26	50	Biased	0.0277	0.0293	0.0016
27	30	Unbiased	0.0294	0.0297	0.0003
28	30	Biased	0.0288	0.0294	0.0006
29	30	Unbiased	0.0269	0.0274	0.0005
30	20	Biased	0.0288	0.0293	0.0005
31	30	Unbiased	0.0283	0.0273	-0.001
33	30	Biased	0.0299	0.0313	0.0014
34	50	Unbiased	0.0289	0.0311	0.0022
35	20	Unbiased	0.0283	0.0312	0.0029
41	30	Biased	0.0295	0.0299	0.0004

Test Statistics (V/µs)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.0272	0.028375	0.0301	0.00125	0.0272	0.02795	0.0296	0.001121	-0.0011	-0.000425	0	0.00049917
20	0.0272	0.02852	0.0299	0.00084169	0.0278	0.02911	0.0312	0.00096315	-0.001	0.00059	0.0029	0.0010126
30	0.0269	0.02879	0.0299	0.00091585	0.0273	0.0291	0.0313	0.0011954	-0.001	0.00031	0.0018	0.00088122
50	0.0268	0.02833	0.0295	0.00088826	0.0293	0.0304	0.0315	0.00073182	0.0011	0.00207	0.0032	0.00061473

Device Test: 22.3 LEVEL|SLOPE_2/RSC_A/12/12/0/0/5/100kHz//@SC_RSC_A_100K





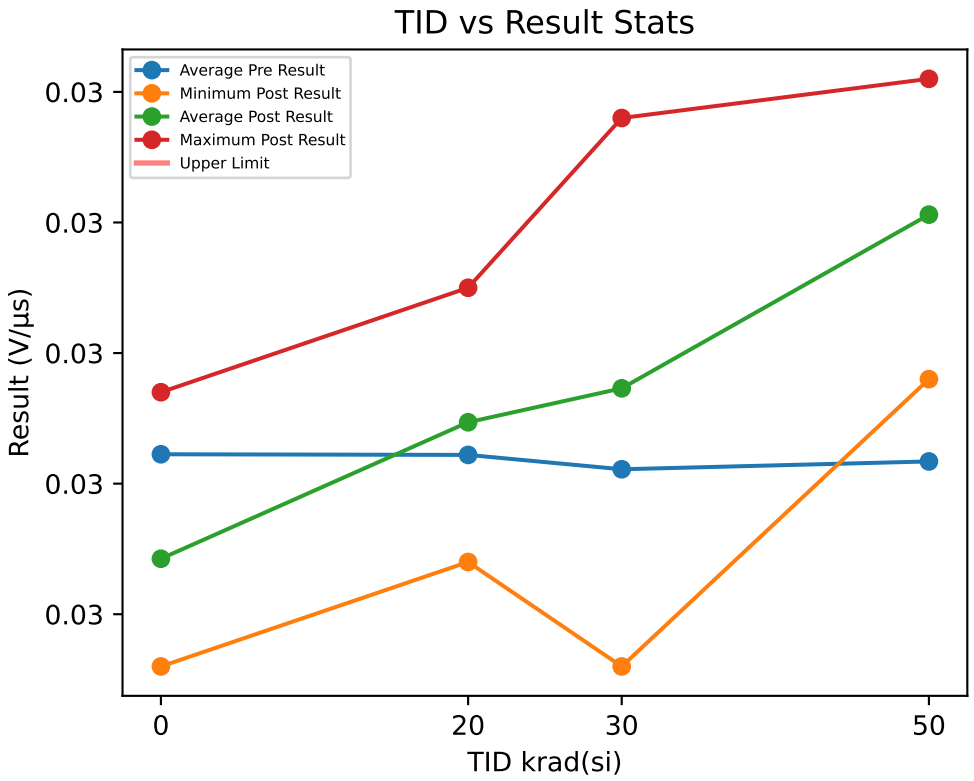
Test Results (No Limits Specified (V/µs))

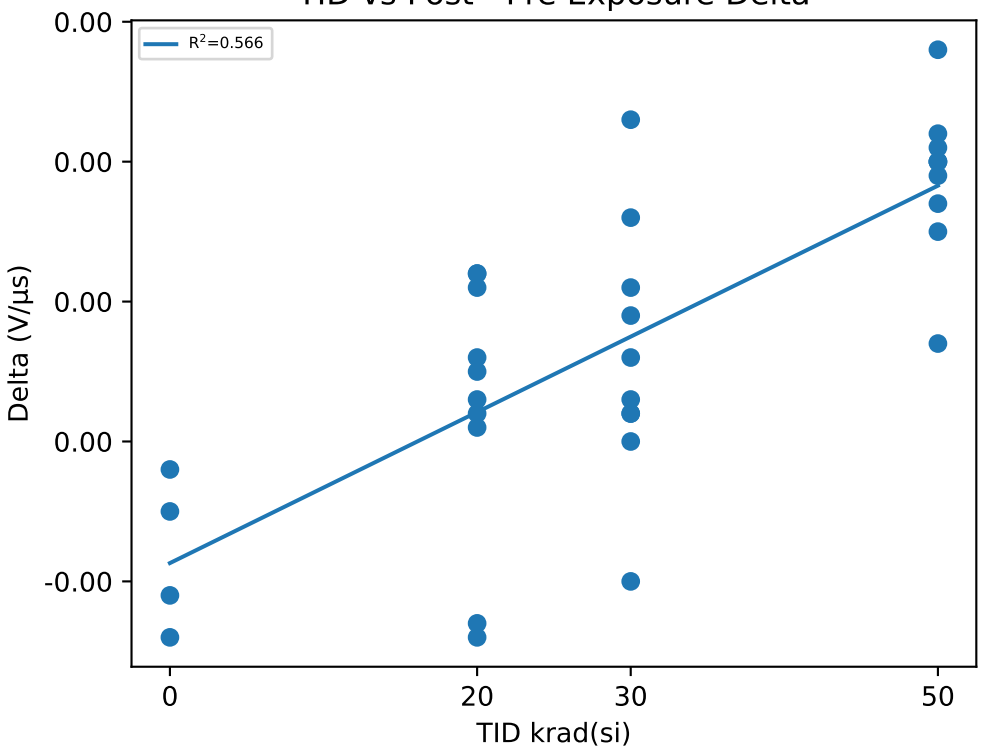
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	0.0294	0.0304	0.001
2	20	Unbiased	0.0276	0.0284	0.0008
3	50	Biased	0.0284	0.0289	0.0005
4	30	Unbiased	0.0288	0.0286	-0.0002
5	50	Unbiased	0.0281	0.0301	0.002
6	30	Biased	0.028	0.0291	0.0011
7	50	Biased	0.029	0.0308	0.0018
8	30	Unbiased	0.0286	0.0277	-0.0009
9	20	Unbiased	0.0285	0.0295	0.001
10	50	Biased	0.0272	0.0291	0.0019
11	30	Biased	0.0275	0.0297	0.0022
12	0	Correlation	0.0279	0.0281	0.0002
13	0	Correlation	0.0271	0.0272	0.0001
14	50	Unbiased	0.0269	0.03	0.0031
15	20	Biased	0.0267	0.028	0.0013
16	20	Unbiased	0.029	0.029	0
17	20	Biased	0.0275	0.0276	0.0001
18	20	Unbiased	0.0268	0.0277	0.0009
19	20	Biased	0.0291	0.0297	0.0006
20	50	Unbiased	0.0287	0.0313	0.0026
21	0	Correlation	0.0299	0.0284	-0.0015
22	50	Unbiased	0.0289	0.0312	0.0023
23	0	Correlation	0.0286	0.0271	-0.0015
24	20	Biased	0.0298	0.0283	-0.0015
26	50	Biased	0.0275	0.0288	0.0013
27	30	Unbiased	0.0294	0.0291	-0.0003
28	30	Biased	0.0279	0.0285	0.0006
29	30	Unbiased	0.0267	0.0276	0.0009
30	20	Biased	0.0281	0.029	0.0009
31	30	Unbiased	0.0275	0.0268	-0.0007
33	30	Biased	0.0293	0.031	0.0017
34	50	Unbiased	0.0291	0.0308	0.0017
35	20	Unbiased	0.0284	0.0294	0.001
41	30	Biased	0.0288	0.0296	0.0008

Test Statistics (V/µs)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.0271	0.028375	0.0299	0.0011871	0.0271	0.0277	0.0284	0.00064807	-0.0015	-0.000675	0.0002	0.0009535
20	0.0267	0.02815	0.0298	0.0010102	0.0276	0.02866	0.0297	0.00076333	-0.0015	0.00051	0.0013	0.00081438
30	0.0267	0.02825	0.0294	0.00087337	0.0268	0.02877	0.031	0.0012129	-0.0009	0.00052	0.0022	0.0010261
50	0.0269	0.02832	0.0294	0.00086384	0.0288	0.03014	0.0313	0.00093357	0.0005	0.00182	0.0031	0.00076129

Device Test: 22.4 LEVEL|SLOPE_2/RSC_A/14/14/0/0/5/100kHz//@SC_RSC_A_100K





Test Results (No Limits Specified (V/µs))

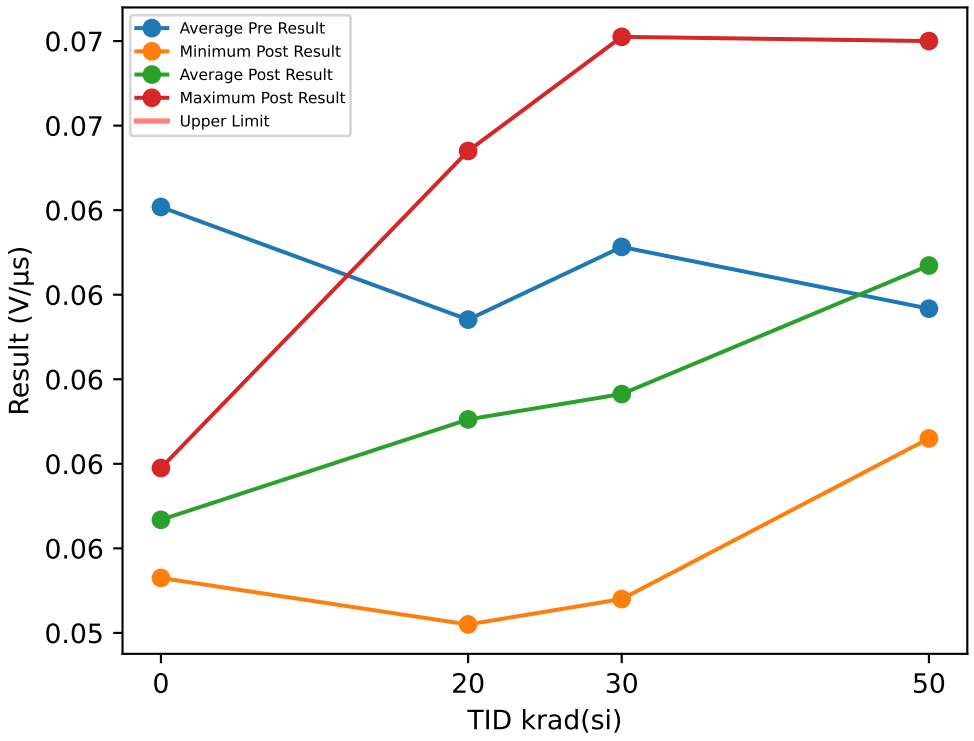
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	0.029	0.0305	0.0015
2	20	Unbiased	0.0276	0.0281	0.0005
3	50	Biased	0.0284	0.0291	0.0007
4	30	Unbiased	0.0286	0.0288	0.0002
5	50	Unbiased	0.028	0.0302	0.0022
6	30	Biased	0.0272	0.0295	0.0023
7	50	Biased	0.0283	0.0304	0.0021
8	30	Unbiased	0.0281	0.0281	0
9	20	Unbiased	0.0289	0.0291	0.0002
10	50	Biased	0.0268	0.0288	0.002
11	30	Biased	0.0277	0.0293	0.0016
12	0	Correlation	0.0279	0.0277	-0.0002
13	0	Correlation	0.0271	0.0266	-0.0005
14	50	Unbiased	0.0271	0.0299	0.0028
15	20	Biased	0.0262	0.0274	0.0012
16	20	Unbiased	0.0301	0.0288	-0.0013
17	20	Biased	0.0278	0.0279	0.0001
18	20	Unbiased	0.0275	0.0278	0.0003
19	20	Biased	0.0283	0.0295	0.0012
20	50	Unbiased	0.0292	0.0309	0.0017
21	0	Correlation	0.0298	0.0287	-0.0011
22	50	Unbiased	0.0288	0.0308	0.002
23	0	Correlation	0.0281	0.0267	-0.0014
24	20	Biased	0.0293	0.0279	-0.0014
26	50	Biased	0.027	0.0289	0.0019
27	30	Unbiased	0.0288	0.0294	0.0006
28	30	Biased	0.0273	0.0284	0.0011
29	30	Unbiased	0.027	0.0273	0.0003
30	20	Biased	0.0281	0.0287	0.0006
31	30	Unbiased	0.0276	0.0266	-0.001
33	30	Biased	0.0299	0.0308	0.0009
34	50	Unbiased	0.0291	0.0311	0.002
35	20	Unbiased	0.0284	0.0295	0.0011
41	30	Biased	0.0289	0.0291	0.0002

Test Statistics (V/µs)

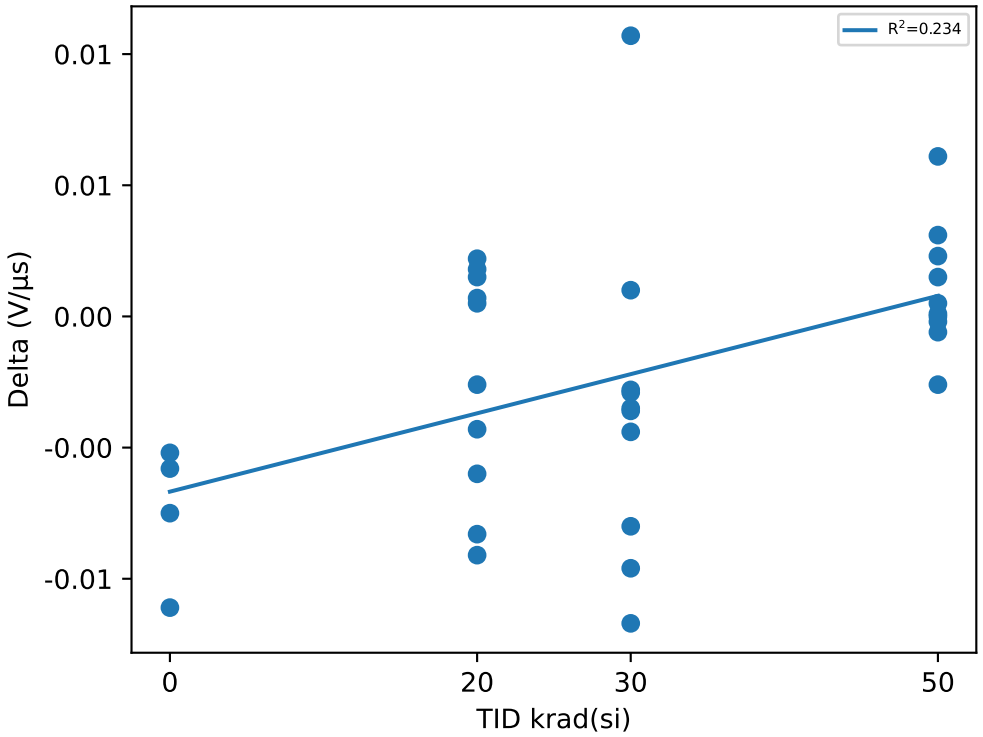
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.0271	0.028225	0.0298	0.0011354	0.0266	0.027425	0.0287	0.00098446	-0.0014	-0.0008	-0.0002	0.00054772
20	0.0262	0.02822	0.0301	0.0010737	0.0274	0.02847	0.0295	0.00074989	-0.0014	0.00025	0.0012	0.00093482
30	0.027	0.02811	0.0299	0.0009243	0.0266	0.02873	0.0308	0.0011963	-0.001	0.00062	0.0023	0.00091627
50	0.0268	0.02817	0.0292	0.00091293	0.0288	0.03006	0.0311	0.00085271	0.0007	0.00189	0.0028	0.00053841

Device Test: 22.5 LEVEL|SLOPE_2/RSC_B/4.5/4.5/0/0/4.5/200kHz//@SC_RSC_B_200K

TID vs Result Stats



TID vs Post - Pre Exposure Delta



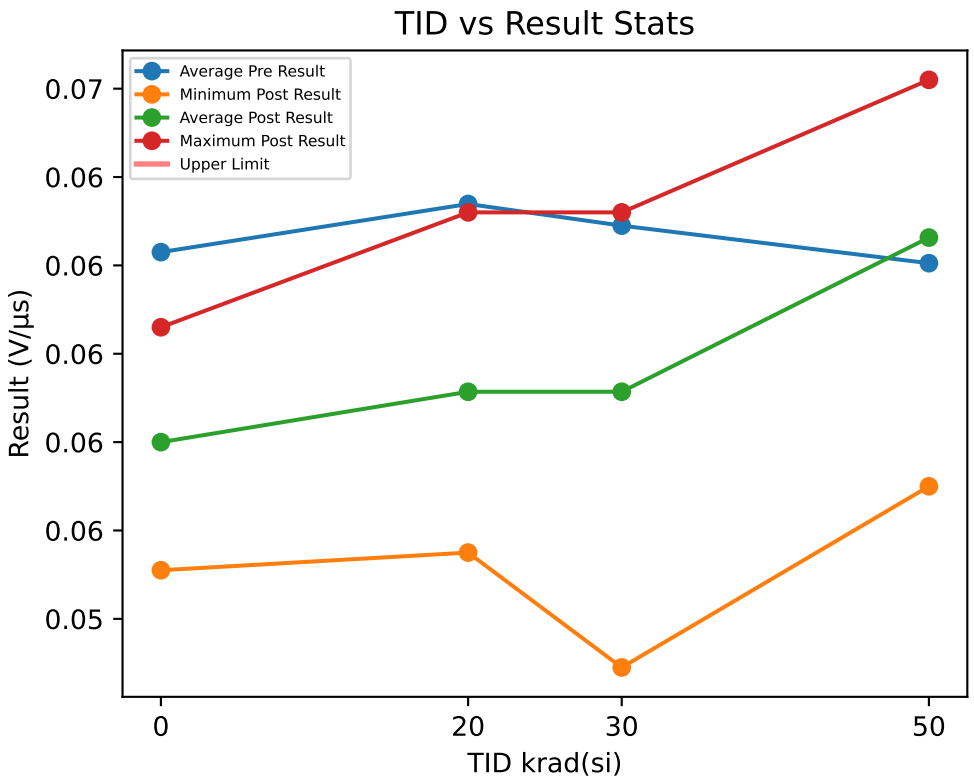
Test Results (No Limits Specified (V/µs))

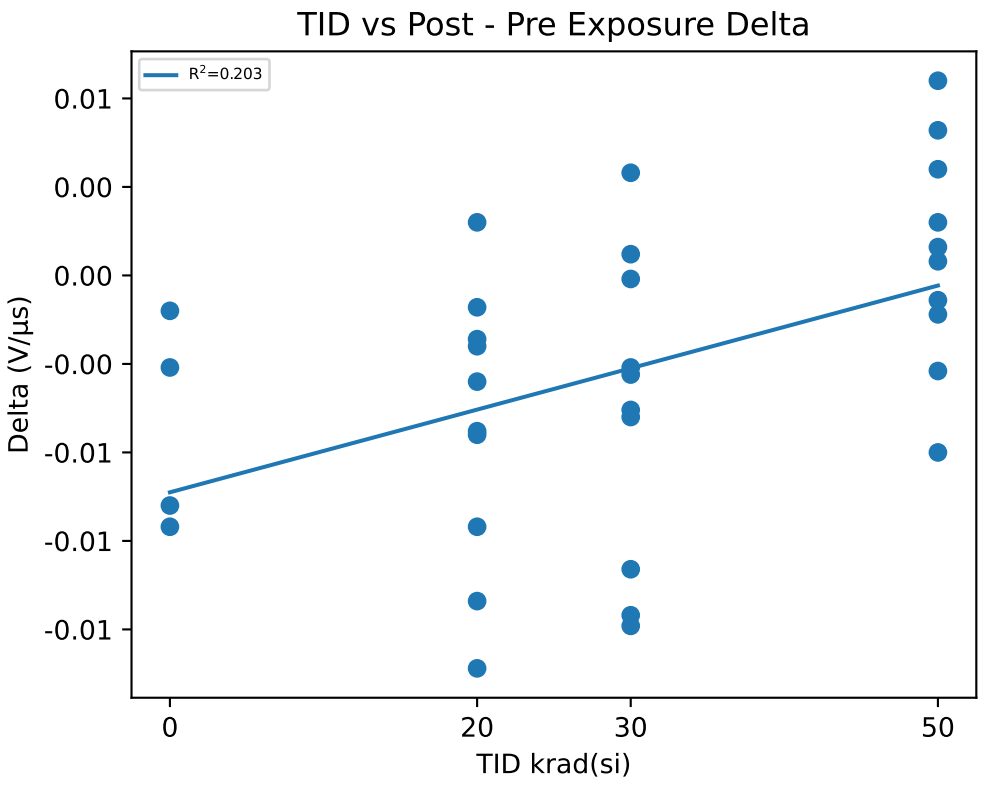
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	0.0636	0.061	-0.0026
2	20	Unbiased	0.059	0.0597	0.0007
3	50	Biased	0.0599	0.0622	0.0023
4	30	Unbiased	0.0655	0.062	-0.0035
5	50	Unbiased	0.0625	0.063	0.0005
6	30	Biased	0.0639	0.061	-0.0029
7	50	Biased	0.0632	0.0626	-0.0006
8	30	Unbiased	0.0637	0.0609	-0.0028
9	20	Unbiased	0.0636	0.0654	0.0018
10	50	Biased	0.0579	0.0594	0.0015
11	30	Biased	0.056	0.057	0.001
12	0	Correlation	0.0631	0.0579	-0.0052
13	0	Correlation	0.0642	0.0567	-0.0075
14	50	Unbiased	0.0602	0.06	-0.0002
15	20	Biased	0.0608	0.0582	-0.0026
16	20	Unbiased	0.0674	0.0583	-0.0091
17	20	Biased	0.0625	0.0542	-0.0083
18	20	Unbiased	0.0625	0.0582	-0.0043
19	20	Biased	0.0572	0.0577	0.0005
20	50	Unbiased	0.0619	0.068	0.0061
21	0	Correlation	0.0679	0.0568	-0.0111
22	50	Unbiased	0.0634	0.0665	0.0031
23	0	Correlation	0.0611	0.0553	-0.0058
24	20	Biased	0.0657	0.0597	-0.006
26	50	Biased	0.0585	0.0586	0.0001
27	30	Unbiased	0.0574	0.0681	0.0107
28	30	Biased	0.0618	0.0582	-0.0036
29	30	Unbiased	0.0646	0.055	-0.0096
30	20	Biased	0.058	0.0602	0.0022
31	30	Unbiased	0.0592	0.0548	-0.0044
33	30	Biased	0.0693	0.0613	-0.008
34	50	Unbiased	0.0656	0.0656	0
35	20	Unbiased	0.0574	0.0589	0.0015
41	30	Biased	0.0699	0.0582	-0.0117

Test Statistics (V/µs)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.0611	0.064075	0.0679	0.0028547	0.0553	0.056675	0.0579	0.0010658	-0.0111	-0.0074	-0.0052	0.002652
20	0.0572	0.06141	0.0674	0.0035445	0.0542	0.05905	0.0654	0.0027862	-0.0091	-0.00236	0.0022	0.0043247
30	0.056	0.06313	0.0699	0.0046366	0.0548	0.05965	0.0681	0.0039357	-0.0117	-0.00348	0.0107	0.0062205
50	0.0579	0.06167	0.0656	0.0024676	0.0586	0.06269	0.068	0.0031476	-0.0026	0.00102	0.0061	0.0023892

Device Test: 22.6 LEVEL|SLOPE_2/RSC_B/5/5/0/0/5/200kHz//@SC_RSC_B_200K





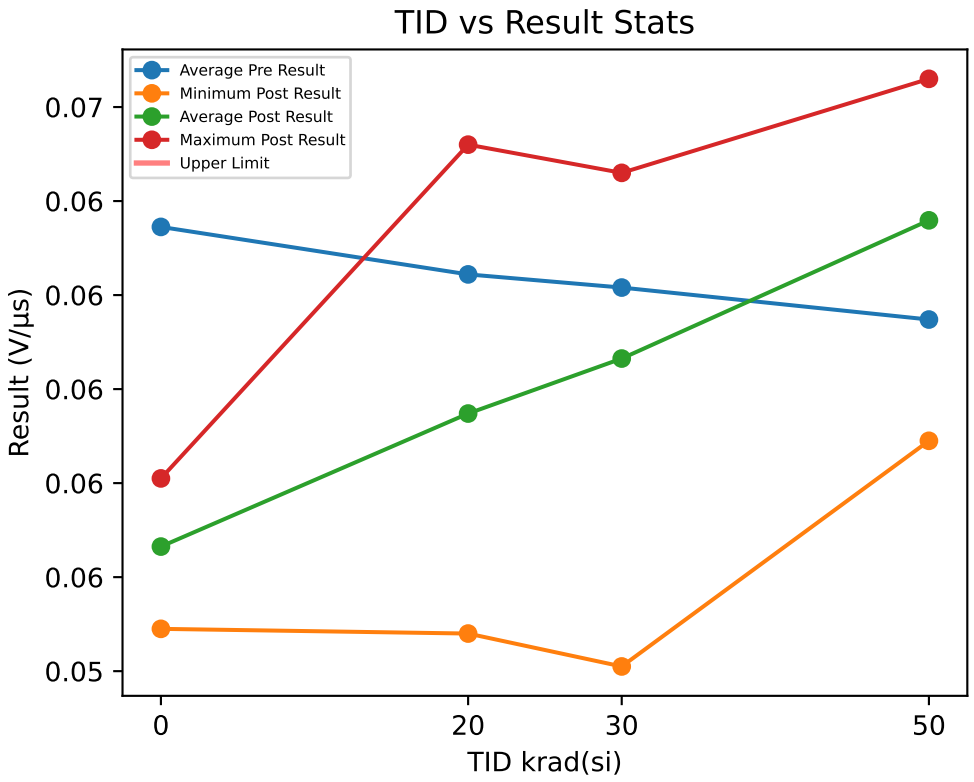
Test Results (No Limits Specified (V/µs))

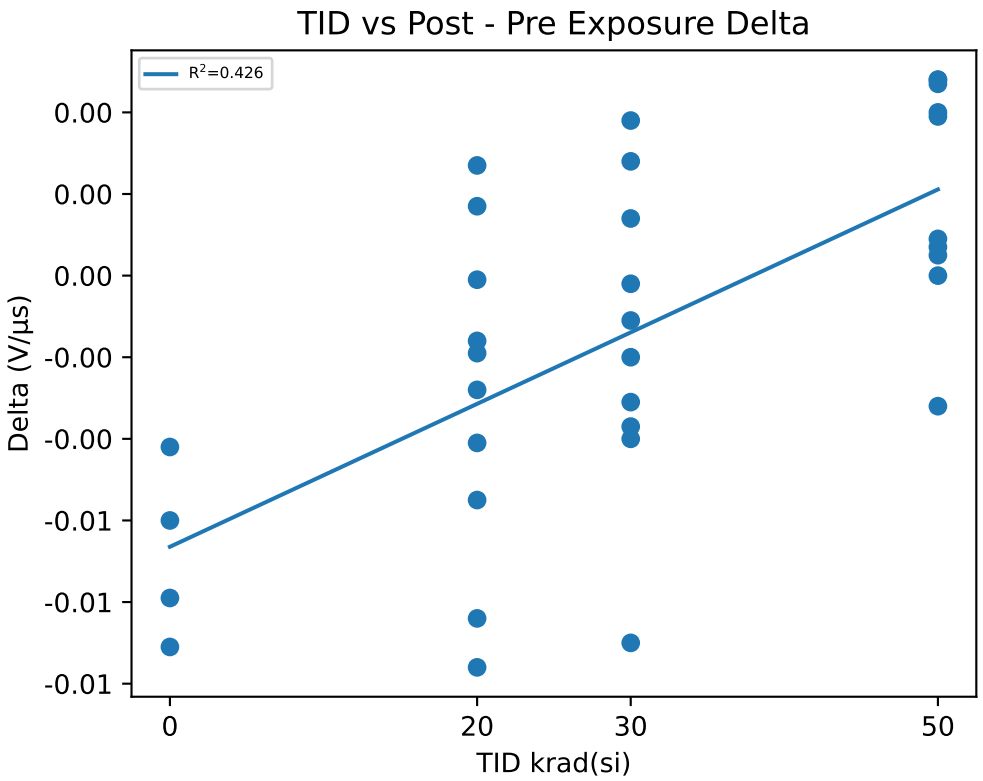
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	0.0662	0.0655	-0.0007
2	20	Unbiased	0.0569	0.0584	0.0015
3	50	Biased	0.0627	0.06	-0.0027
4	30	Unbiased	0.0683	0.0587	-0.0096
5	50	Unbiased	0.0664	0.0614	-0.005
6	30	Biased	0.0603	0.0632	0.0029
7	50	Biased	0.0614	0.0622	0.0008
8	30	Unbiased	0.0665	0.0582	-0.0083
9	20	Unbiased	0.0677	0.0632	-0.0045
10	50	Biased	0.0552	0.0593	0.0041
11	30	Biased	0.0586	0.0585	-0.0001
12	0	Correlation	0.0637	0.0566	-0.0071
13	0	Correlation	0.0623	0.0597	-0.0026
14	50	Unbiased	0.0619	0.0649	0.003
15	20	Biased	0.0638	0.0594	-0.0044
16	20	Unbiased	0.0674	0.0582	-0.0092
17	20	Biased	0.0626	0.0555	-0.0071
18	20	Unbiased	0.0596	0.0576	-0.002
19	20	Biased	0.0615	0.0597	-0.0018
20	50	Unbiased	0.0656	0.066	0.0004
21	0	Correlation	0.0671	0.0606	-0.0065
22	50	Unbiased	0.0607	0.0662	0.0055
23	0	Correlation	0.0561	0.0551	-0.001
24	20	Biased	0.0701	0.059	-0.0111
26	50	Biased	0.0555	0.057	0.0015
27	30	Unbiased	0.0625	0.0631	0.0006
28	30	Biased	0.0638	0.06	-0.0038
29	30	Unbiased	0.0592	0.0566	-0.0026
30	20	Biased	0.0617	0.0587	-0.003
31	30	Unbiased	0.0557	0.0529	-0.0028
33	30	Biased	0.067	0.063	-0.004
34	50	Unbiased	0.0649	0.0638	-0.0011
35	20	Unbiased	0.0626	0.0617	-0.0009
41	30	Biased	0.0671	0.0572	-0.0099

Test Statistics (V/µs)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.0561	0.0623	0.0671	0.0045986	0.0551	0.058	0.0606	0.0025833	-0.0071	-0.0043	-0.001	0.0029698
20	0.0569	0.06339	0.0701	0.0040001	0.0555	0.05914	0.0632	0.0021261	-0.0111	-0.00425	0.0015	0.0038951
30	0.0557	0.0629	0.0683	0.0043246	0.0529	0.05914	0.0632	0.0033073	-0.0099	-0.00376	0.0029	0.0043653
50	0.0552	0.06205	0.0664	0.0040741	0.057	0.06263	0.0662	0.0031669	-0.005	0.00058	0.0055	0.0031576

Device Test: 22.7 LEVEL|SLOPE_2/RSC_B/12/12/0/0/5/200kHz//@SC_RSC_B_200K





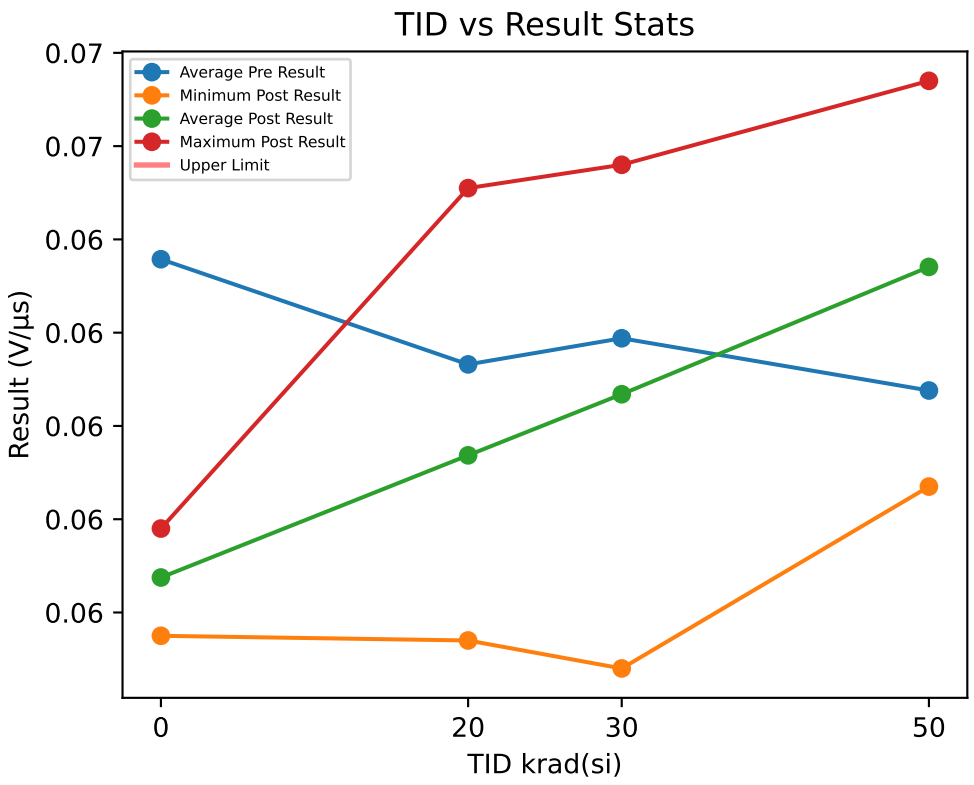
Test Results (No Limits Specified (V/µs))

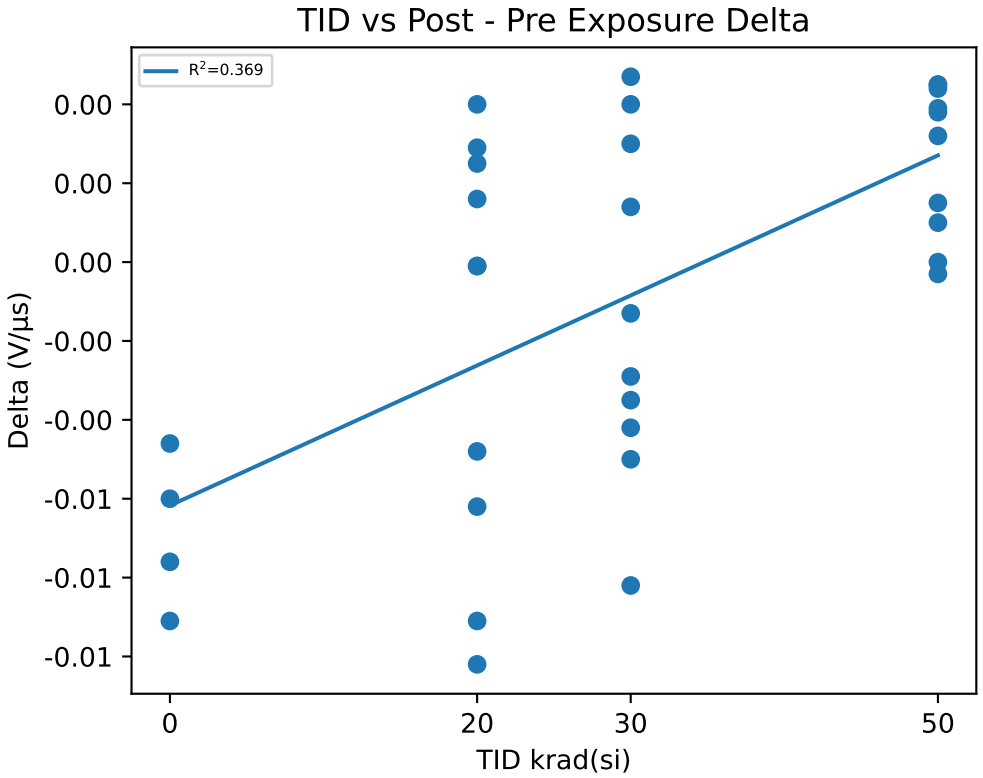
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	0.0659	0.0627	-0.0032
2	20	Unbiased	0.0602	0.0583	-0.0019
3	50	Biased	0.0595	0.0634	0.0039
4	30	Unbiased	0.0627	0.0625	-0.0002
5	50	Unbiased	0.0615	0.062	0.0005
6	30	Biased	0.0605	0.0643	0.0038
7	50	Biased	0.0629	0.0636	0.0007
8	30	Unbiased	0.0617	0.0586	-0.0031
9	20	Unbiased	0.0625	0.0652	0.0027
10	50	Biased	0.0559	0.0607	0.0048
11	30	Biased	0.0608	0.0597	-0.0011
12	0	Correlation	0.0637	0.0577	-0.006
13	0	Correlation	0.0638	0.0559	-0.0079
14	50	Unbiased	0.0616	0.0663	0.0047
15	20	Biased	0.0615	0.0574	-0.0041
16	20	Unbiased	0.0682	0.0586	-0.0096
17	20	Biased	0.0632	0.0548	-0.0084
18	20	Unbiased	0.0608	0.0592	-0.0016
19	20	Biased	0.0623	0.064	0.0017
20	50	Unbiased	0.0657	0.0666	0.0009
21	0	Correlation	0.0672	0.0581	-0.0091
22	50	Unbiased	0.0616	0.0656	0.004
23	0	Correlation	0.0591	0.0549	-0.0042
24	20	Biased	0.0641	0.0586	-0.0055
26	50	Biased	0.0589	0.0589	0
27	30	Unbiased	0.0632	0.0646	0.0014
28	30	Biased	0.058	0.0608	0.0028
29	30	Unbiased	0.0621	0.0584	-0.0037
30	20	Biased	0.0624	0.0596	-0.0028
31	30	Unbiased	0.0561	0.0541	-0.002
33	30	Biased	0.0677	0.0637	-0.004
34	50	Unbiased	0.0613	0.0661	0.0048
35	20	Unbiased	0.0592	0.0591	-0.0001
41	30	Biased	0.0688	0.0598	-0.009

Test Statistics (V/µs)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.0591	0.06345	0.0672	0.0033252	0.0549	0.05665	0.0581	0.0015089	-0.0091	-0.0068	-0.0042	0.0021525
20	0.0592	0.06244	0.0682	0.002486	0.0548	0.05948	0.0652	0.0030287	-0.0096	-0.00296	0.0027	0.0040327
30	0.0561	0.06216	0.0688	0.003873	0.0541	0.06065	0.0646	0.0032569	-0.009	-0.00151	0.0038	0.0037563
50	0.0559	0.06148	0.0659	0.0030025	0.0589	0.06359	0.0666	0.0025916	-0.0032	0.00211	0.0048	0.0027213

Device Test: 22.8 LEVEL|SLOPE_2/RSC_B/14/14/0/0/5/200kHz//@SC_RSC_B_200K





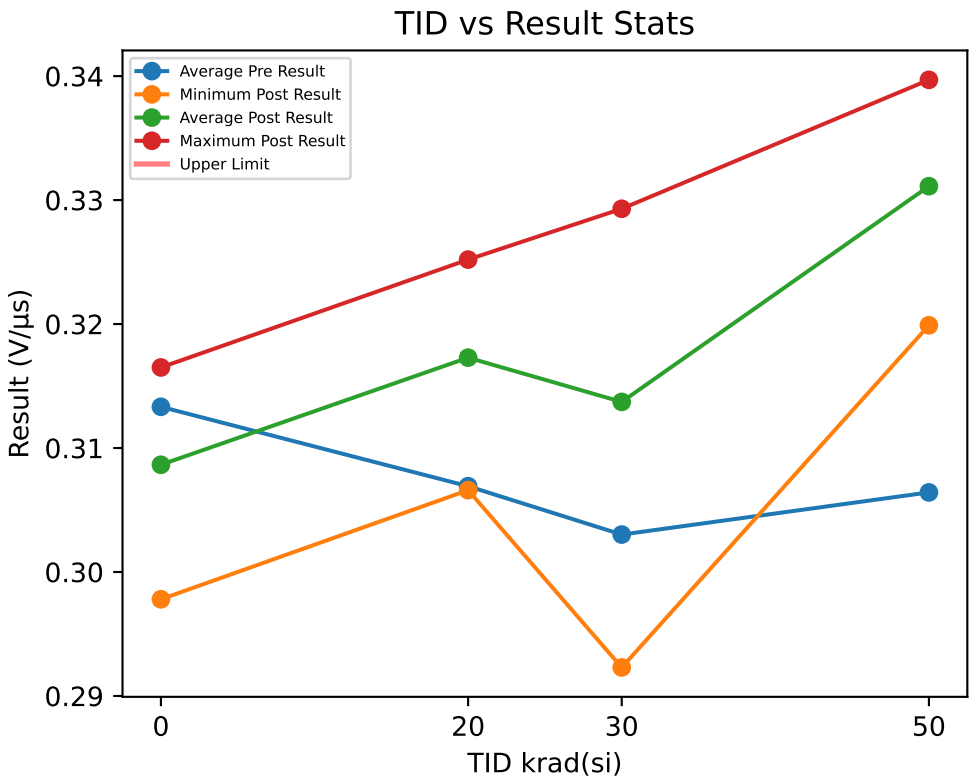
Test Results (No Limits Specified (V/µs))

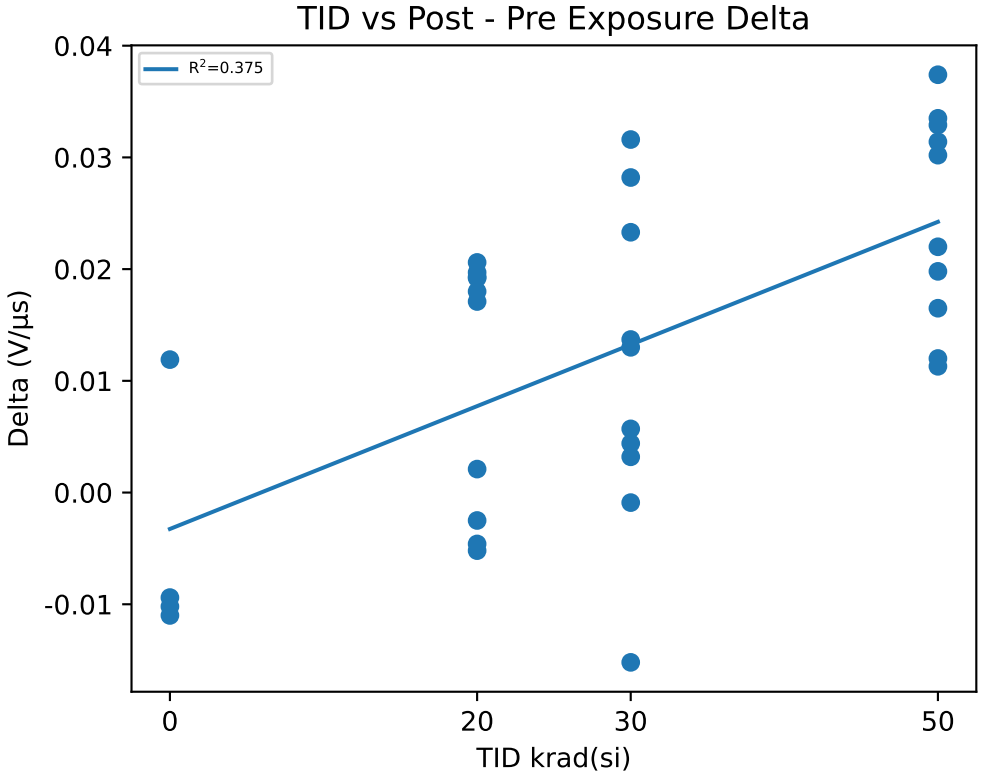
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	0.0638	0.0638	0
2	20	Unbiased	0.0596	0.0595	-0.0001
3	50	Biased	0.059	0.0635	0.0045
4	30	Unbiased	0.0634	0.0621	-0.0013
5	50	Unbiased	0.0612	0.0627	0.0015
6	30	Biased	0.0608	0.0648	0.004
7	50	Biased	0.0638	0.0635	-0.0003
8	30	Unbiased	0.0618	0.0583	-0.0035
9	20	Unbiased	0.0635	0.0651	0.0016
10	50	Biased	0.0576	0.0608	0.0032
11	30	Biased	0.0551	0.0598	0.0047
12	0	Correlation	0.0654	0.0578	-0.0076
13	0	Correlation	0.0624	0.0564	-0.006
14	50	Unbiased	0.0578	0.0622	0.0044
15	20	Biased	0.0612	0.0564	-0.0048
16	20	Unbiased	0.069	0.0588	-0.0102
17	20	Biased	0.0645	0.0554	-0.0091
18	20	Unbiased	0.0543	0.0583	0.004
19	20	Biased	0.0591	0.062	0.0029
20	50	Unbiased	0.0629	0.0674	0.0045
21	0	Correlation	0.0664	0.0573	-0.0091
22	50	Unbiased	0.0621	0.066	0.0039
23	0	Correlation	0.0601	0.0555	-0.0046
24	20	Biased	0.0649	0.0587	-0.0062
26	50	Biased	0.0577	0.0587	0.001
27	30	Unbiased	0.0626	0.0656	0.003
28	30	Biased	0.0594	0.0608	0.0014
29	30	Unbiased	0.062	0.057	-0.005
30	20	Biased	0.0575	0.06	0.0025
31	30	Unbiased	0.059	0.0548	-0.0042
33	30	Biased	0.0673	0.0644	-0.0029
34	50	Unbiased	0.0617	0.0655	0.0038
35	20	Unbiased	0.0596	0.0595	-0.0001
41	30	Biased	0.0674	0.0592	-0.0082

Test Statistics (V/µs)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.0601	0.063575	0.0664	0.0028733	0.0555	0.05675	0.0578	0.0010149	-0.0091	-0.006825	-0.0046	0.00195
20	0.0543	0.06132	0.069	0.0042347	0.0554	0.05937	0.0651	0.0027219	-0.0102	-0.00195	0.004	0.005202
30	0.0551	0.06188	0.0674	0.003716	0.0548	0.06068	0.0656	0.0035558	-0.0082	-0.0012	0.0047	0.0043061
50	0.0576	0.06076	0.0638	0.0025198	0.0587	0.06341	0.0674	0.0025414	-0.0003	0.00265	0.0045	0.0019109

Device Test: 22.9 LEVEL|SLOPE_2/RSC_C/4.5/4.5/0/0/4.5/500kHz//@SC_RSC_C_500K





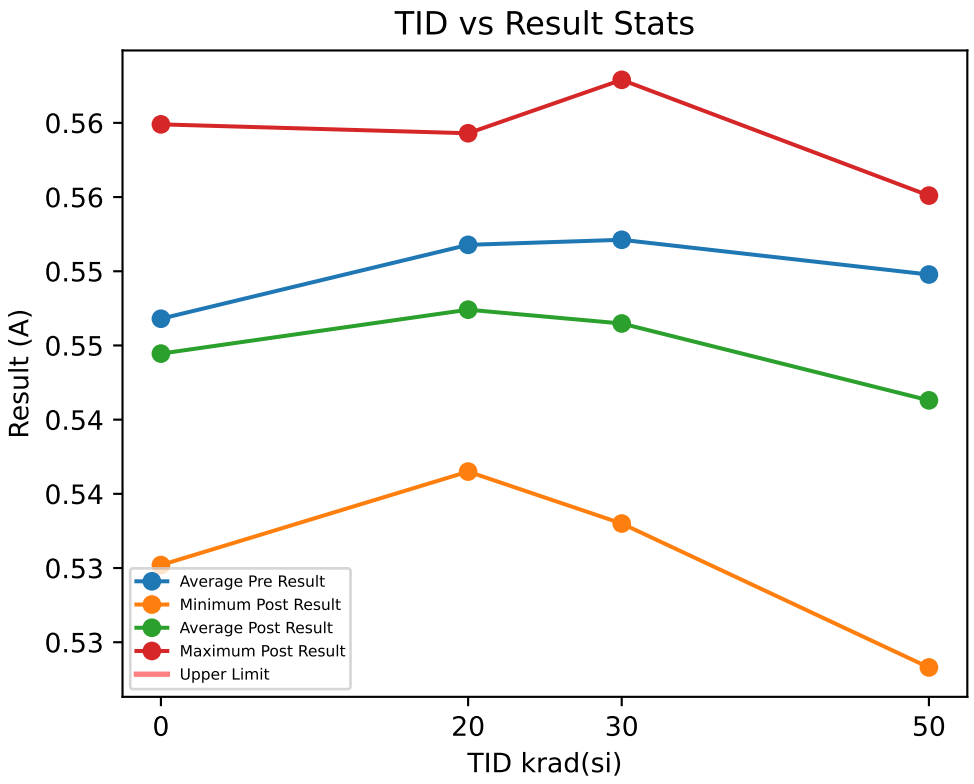
Test Results (No Limits Specified (V/µs))

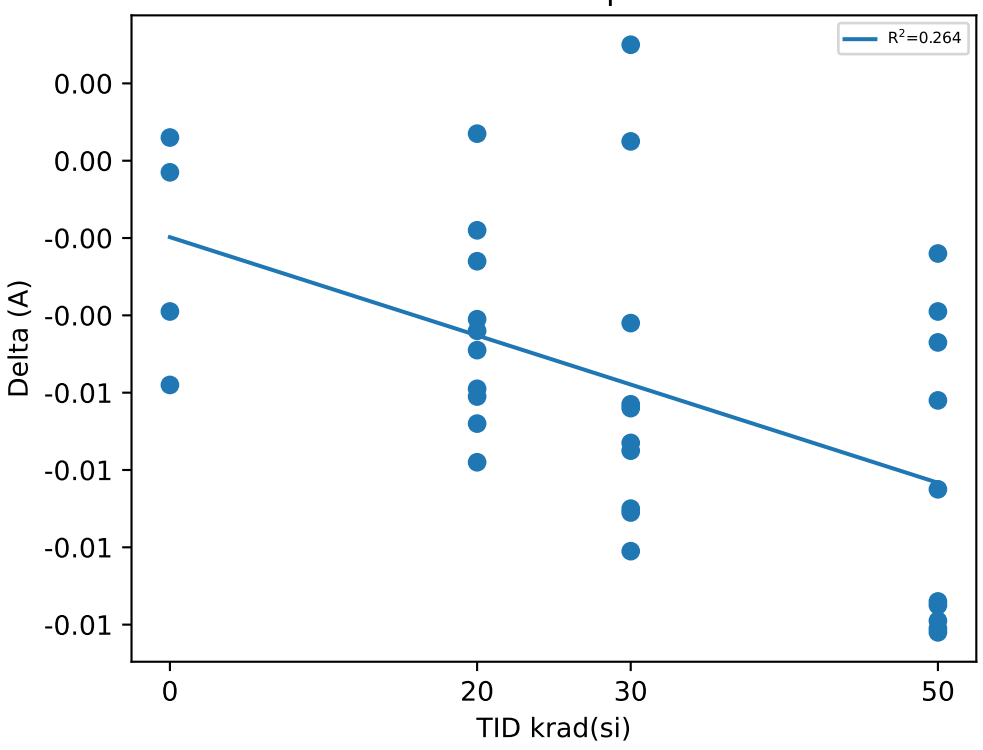
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	0.3277	0.3397	0.012
2	20	Unbiased	0.3003	0.3183	0.018
3	50	Biased	0.2947	0.3321	0.0374
4	30	Unbiased	0.3056	0.3088	0.0032
5	50	Unbiased	0.3236	0.3349	0.0113
6	30	Biased	0.2955	0.3237	0.0282
7	50	Biased	0.2943	0.3278	0.0335
8	30	Unbiased	0.3121	0.3112	-0.0009
9	20	Unbiased	0.3214	0.3189	-0.0025
10	50	Biased	0.292	0.3249	0.0329
11	30	Biased	0.2975	0.3291	0.0316
12	0	Correlation	0.3234	0.3124	-0.011
13	0	Correlation	0.3181	0.3079	-0.0102
14	50	Unbiased	0.2979	0.3199	0.022
15	20	Biased	0.2938	0.313	0.0192
16	20	Unbiased	0.3234	0.3182	-0.0052
17	20	Biased	0.3112	0.3066	-0.0046
18	20	Unbiased	0.2988	0.3185	0.0197
19	20	Biased	0.3002	0.3195	0.0193
20	50	Unbiased	0.3202	0.3367	0.0165
21	0	Correlation	0.3259	0.3165	-0.0094
22	50	Unbiased	0.3061	0.3375	0.0314
23	0	Correlation	0.2859	0.2978	0.0119
24	20	Biased	0.3128	0.3149	0.0021
26	50	Biased	0.2906	0.3208	0.0302
27	30	Unbiased	0.2908	0.3141	0.0233
28	30	Biased	0.305	0.3187	0.0137
29	30	Unbiased	0.3061	0.3118	0.0057
30	20	Biased	0.2992	0.3198	0.0206
31	30	Unbiased	0.2852	0.2982	0.013
33	30	Biased	0.3249	0.3293	0.0044
34	50	Unbiased	0.3171	0.3369	0.0198
35	20	Unbiased	0.3081	0.3252	0.0171
41	30	Biased	0.3075	0.2923	-0.0152

Test Statistics (V/µs)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.2859	0.31333	0.3259	0.01857	0.2978	0.30865	0.3165	0.0080409	-0.011	-0.004675	0.0119	0.011069
20	0.2938	0.30692	0.3234	0.010123	0.3066	0.31729	0.3252	0.0049222	-0.0052	0.01037	0.0206	0.011321
30	0.2852	0.30302	0.3249	0.011329	0.2923	0.31372	0.3293	0.012192	-0.0152	0.0107	0.0316	0.014308
50	0.2906	0.30642	0.3277	0.014403	0.3199	0.33112	0.3397	0.0072741	0.0113	0.0247	0.0374	0.0095481

Device Test: 23.1 CURRENT|SOURCE/OUTH/4.5/4.5/0/0/4.5/500kHz//@OUT_IOH_4P5V





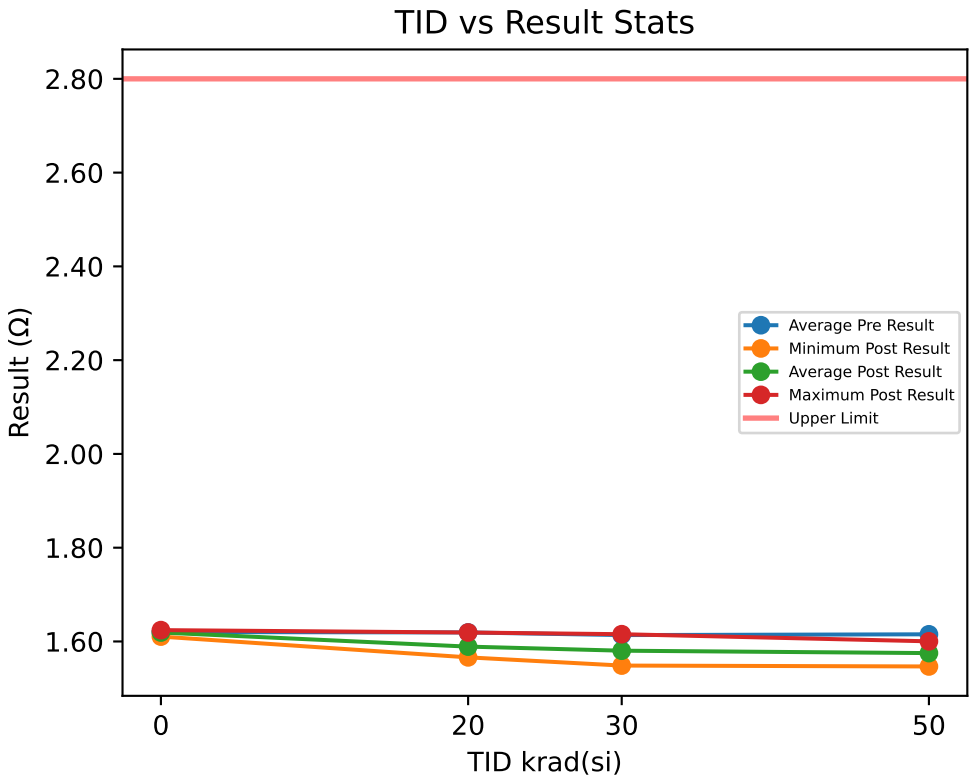
Test Results (No Limits Specified (A))

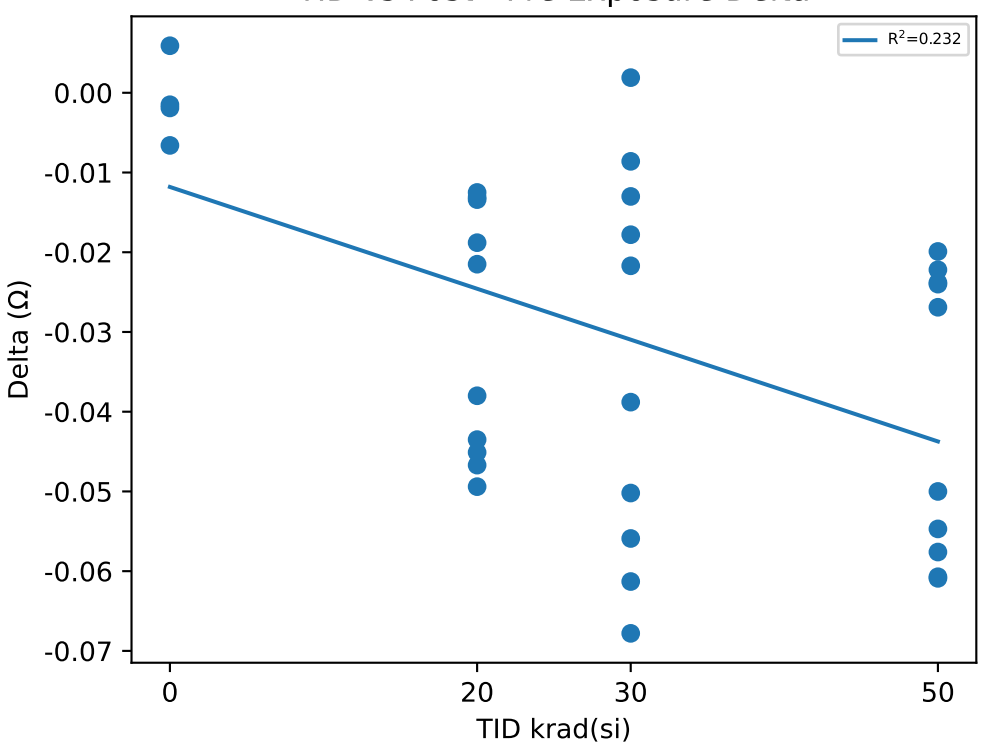
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	0.5672	0.5551	-0.0121
2	20	Unbiased	0.5608	0.5567	-0.0041
3	50	Biased	0.5638	0.5519	-0.0119
4	30	Unbiased	0.572	0.5629	-0.0091
5	50	Unbiased	0.5416	0.5294	-0.0122
6	30	Biased	0.5419	0.5377	-0.0042
7	50	Biased	0.5353	0.5239	-0.0114
8	30	Unbiased	0.566	0.5587	-0.0073
9	20	Unbiased	0.5637	0.5593	-0.0044
10	50	Biased	0.5612	0.555	-0.0062
11	30	Biased	0.5602	0.5527	-0.0075
12	0	Correlation	0.536	0.5302	-0.0058
13	0	Correlation	0.5463	0.5424	-0.0039
14	50	Unbiased	0.547	0.5431	-0.0039
15	20	Biased	0.5424	0.5365	-0.0059
16	20	Unbiased	0.553	0.5469	-0.0061
17	20	Biased	0.5463	0.5437	-0.0026
18	20	Unbiased	0.5387	0.5394	0.0007
19	20	Biased	0.5645	0.5567	-0.0078
20	50	Unbiased	0.5348	0.5233	-0.0115
21	0	Correlation	0.5593	0.5599	0.0006
22	50	Unbiased	0.549	0.5443	-0.0047
23	0	Correlation	0.5456	0.5453	-0.0003
24	20	Biased	0.5447	0.5398	-0.0049
26	50	Biased	0.5375	0.5351	-0.0024
27	30	Unbiased	0.5432	0.5368	-0.0064
28	30	Biased	0.5431	0.533	-0.0101
29	30	Unbiased	0.5617	0.5527	-0.009
30	20	Biased	0.5399	0.5381	-0.0018
31	30	Unbiased	0.5452	0.5457	0.0005
33	30	Biased	0.5451	0.5388	-0.0063
34	50	Unbiased	0.5604	0.5519	-0.0085
35	20	Unbiased	0.5638	0.557	-0.0068
41	30	Biased	0.5428	0.5458	0.003

Test Statistics (A)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.536	0.5468	0.5593	0.009567	0.5302	0.54445	0.5599	0.012202	-0.0058	-0.00235	0.0006	0.0030116
20	0.5387	0.55178	0.5645	0.010602	0.5365	0.54741	0.5593	0.009115	-0.0078	-0.00437	0.0007	0.0025561
30	0.5419	0.55212	0.572	0.01152	0.533	0.54648	0.5629	0.010049	-0.0101	-0.00564	0.003	0.0042792
50	0.5348	0.54978	0.5672	0.012487	0.5233	0.5413	0.5551	0.012569	-0.0122	-0.00848	-0.0024	0.0038545

Device Test: 23.10 LEVEL|LS_RDSON/OUTL/12/12/100/0/5/500kHz//@ROL





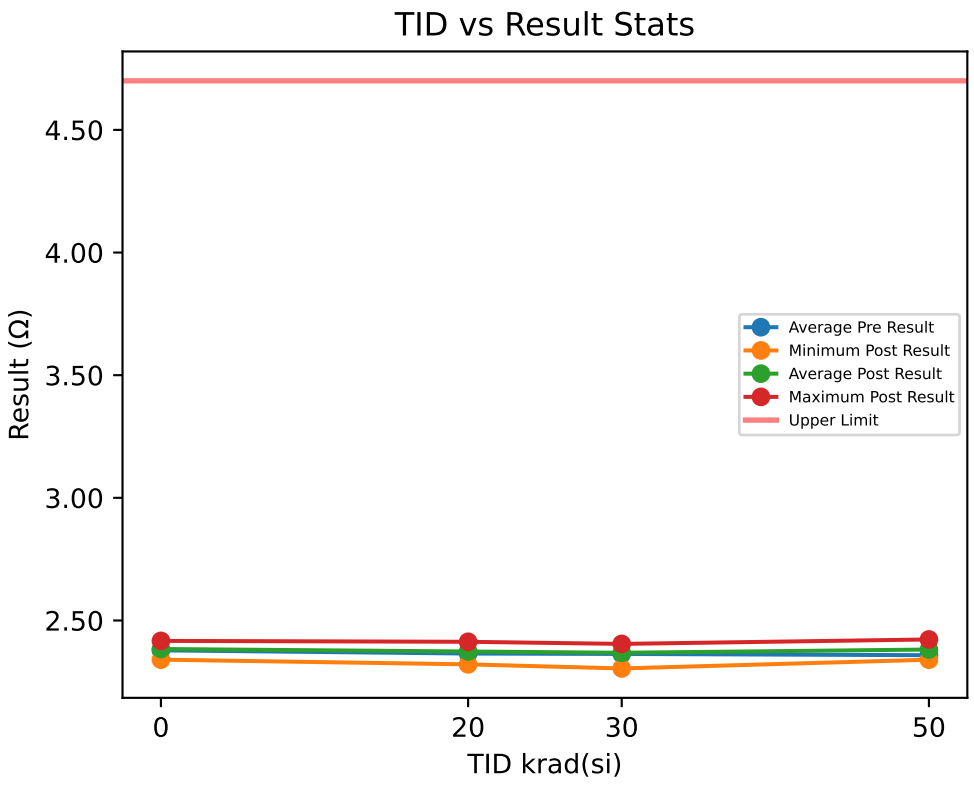
Test Results (Upper Limit = 2.8 (Ω))

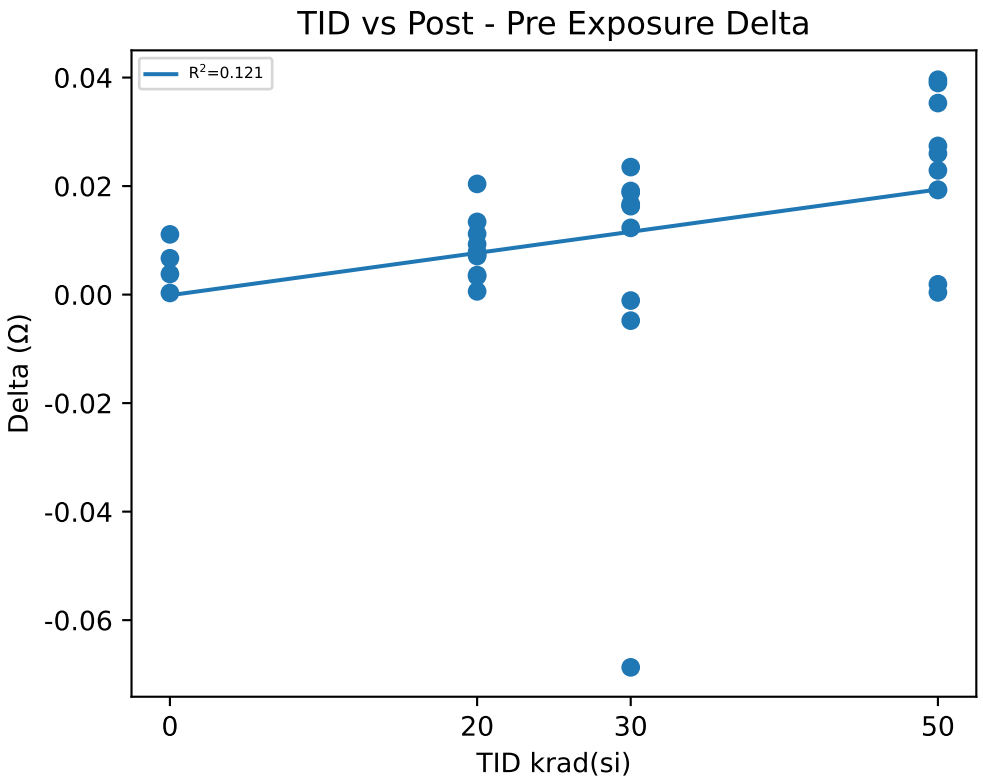
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	1.6014	1.5467	-0.0547
2	20	Unbiased	1.6068	1.5937	-0.0131
3	50	Biased	1.6063	1.5563	-0.05
4	30	Unbiased	1.6066	1.5888	-0.0178
5	50	Unbiased	1.6153	1.5931	-0.0222
6	30	Biased	1.6192	1.569	-0.0502
7	50	Biased	1.6195	1.5619	-0.0576
8	30	Unbiased	1.6058	1.5972	-0.0086
9	20	Unbiased	1.6146	1.6012	-0.0134
10	50	Biased	1.6244	1.5637	-0.0607
11	30	Biased	1.6045	1.5486	-0.0559
12	0	Correlation	1.6252	1.6186	-0.0066
13	0	Correlation	1.625	1.6231	-0.0019
14	50	Unbiased	1.614	1.5941	-0.0199
15	20	Biased	1.6135	1.57	-0.0435
16	20	Unbiased	1.6298	1.611	-0.0188
17	20	Biased	1.6243	1.5863	-0.038
18	20	Unbiased	1.6316	1.6191	-0.0125
19	20	Biased	1.6128	1.5661	-0.0467
20	50	Unbiased	1.6272	1.6003	-0.0269
21	0	Correlation	1.6045	1.6104	0.0059
22	50	Unbiased	1.6128	1.5888	-0.024
23	0	Correlation	1.6257	1.6242	-0.0015
24	20	Biased	1.6306	1.5855	-0.0451
26	50	Biased	1.6233	1.5624	-0.0609
27	30	Unbiased	1.6171	1.6041	-0.013
28	30	Biased	1.627	1.5592	-0.0678
29	30	Unbiased	1.6012	1.5795	-0.0217
30	20	Biased	1.6201	1.5707	-0.0494
31	30	Unbiased	1.6136	1.6155	0.0019
33	30	Biased	1.633	1.5717	-0.0613
34	50	Unbiased	1.6086	1.5848	-0.0238
35	20	Unbiased	1.6082	1.5867	-0.0215
41	30	Biased	1.6083	1.5695	-0.0388

Test Statistics (Ω)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.6045	1.6201	1.6257	0.010404	1.6104	1.6191	1.6242	0.0062702	-0.0066	-0.001025	0.0059	0.0051649
20	1.6068	1.6192	1.6316	0.0093824	1.5661	1.589	1.6191	0.017657	-0.0494	-0.0302	-0.0125	0.015614
30	1.6012	1.6136	1.633	0.010403	1.5486	1.5803	1.6155	0.020903	-0.0678	-0.03332	0.0019	0.024578
50	1.6014	1.6153	1.6272	0.0083871	1.5467	1.5752	1.6003	0.018936	-0.0609	-0.04007	-0.0199	0.017957

Device Test: 23.11 LEVEL|HS_RDSON/OUTH/14/14/100/0/5/500kHz//@ROH





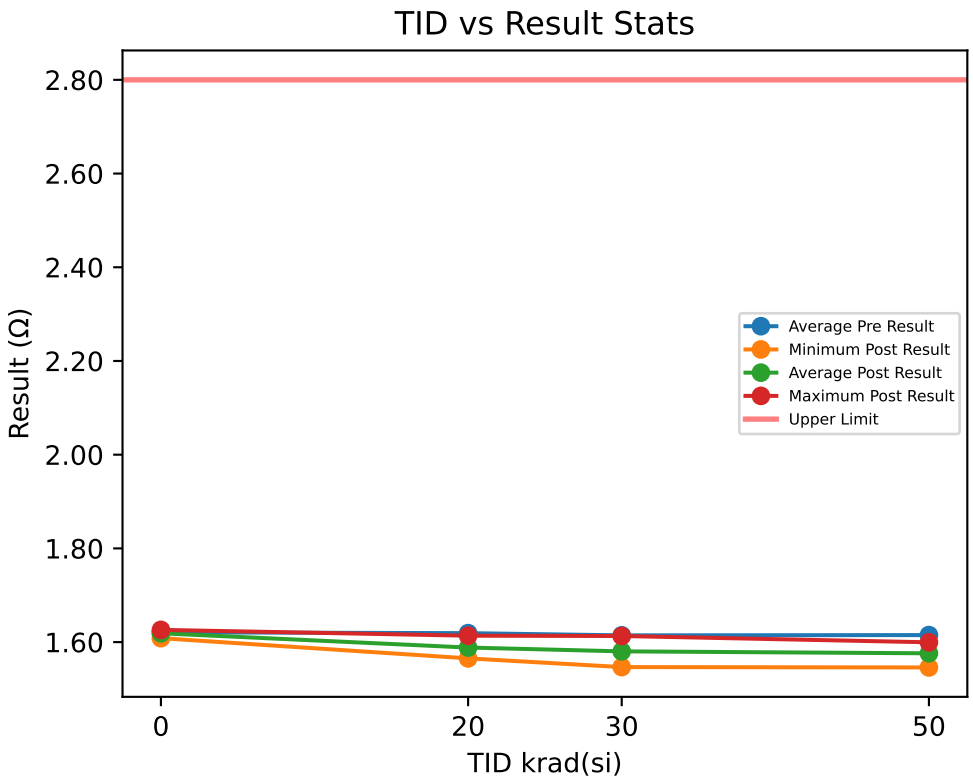
Test Results (Upper Limit = 4.7 (Ω))

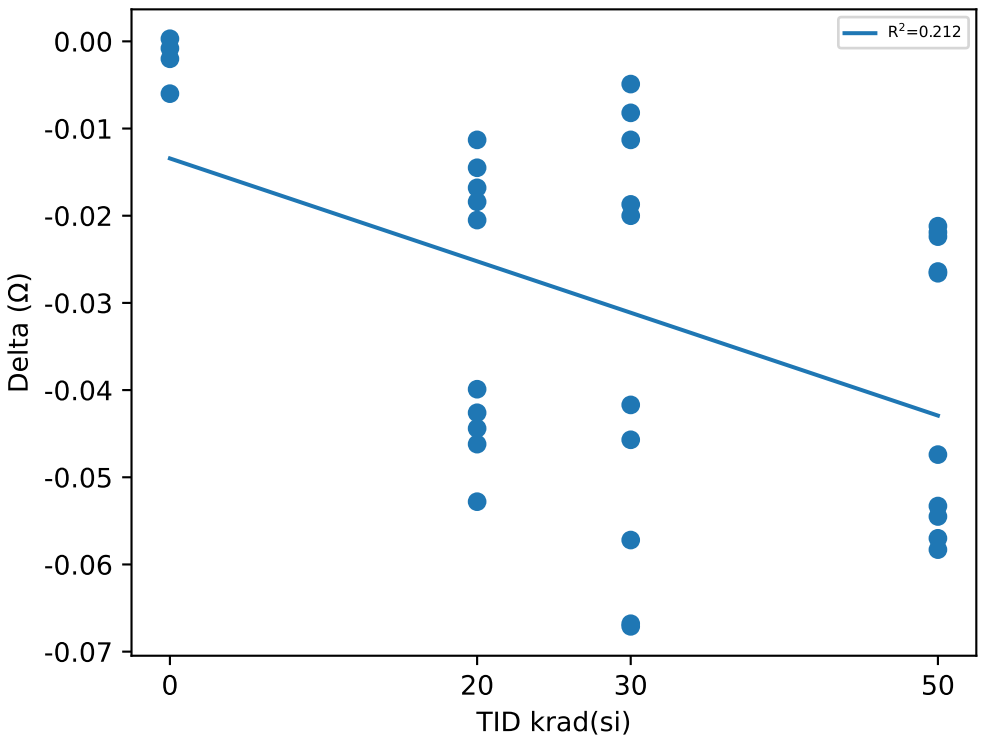
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	2.3215	2.3605	0.039
2	20	Unbiased	2.3333	2.3445	0.0112
3	50	Biased	2.3365	2.3718	0.0353
4	30	Unbiased	2.3196	2.3363	0.0167
5	50	Unbiased	2.3852	2.4045	0.0193
6	30	Biased	2.3765	2.3928	0.0163
7	50	Biased	2.383	2.4226	0.0396
8	30	Unbiased	2.3168	2.3403	0.0235
9	20	Unbiased	2.3585	2.3664	0.0079
10	50	Biased	2.3509	2.3769	0.026
11	30	Biased	2.3498	2.3662	0.0164
12	0	Correlation	2.4057	2.4168	0.0111
13	0	Correlation	2.3908	2.3975	0.0067
14	50	Unbiased	2.3599	2.3618	0.0019
15	20	Biased	2.4038	2.4131	0.0093
16	20	Unbiased	2.3635	2.3769	0.0134
17	20	Biased	2.3931	2.4005	0.0074
18	20	Unbiased	2.3893	2.3899	0.0006
19	20	Biased	2.3393	2.3597	0.0204
20	50	Unbiased	2.3982	2.4211	0.0229
21	0	Correlation	2.34	2.3403	0.0003
22	50	Unbiased	2.3526	2.353	0.0004
23	0	Correlation	2.3765	2.3803	0.0038
24	20	Biased	2.3853	2.3924	0.0071
26	50	Biased	2.3757	2.4031	0.0274
27	30	Unbiased	2.3958	2.391	-0.0048
28	30	Biased	2.3795	2.3986	0.0191
29	30	Unbiased	2.3497	2.3685	0.0188
30	20	Biased	2.3679	2.3715	0.0036
31	30	Unbiased	2.3821	2.381	-0.0011
33	30	Biased	2.3922	2.4045	0.0123
34	50	Unbiased	2.3208	2.3401	0.0193
35	20	Unbiased	2.3177	2.3211	0.0034
41	30	Biased	2.3731	2.3044	-0.0687

Test Statistics (Ω)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.34	2.3782	2.4057	0.028149	2.3403	2.3837	2.4168	0.032564	0.0003	0.005475	0.0111	0.0045727
20	2.3177	2.3652	2.4038	0.028388	2.3211	2.3736	2.4131	0.027419	0.0006	0.00843	0.0204	0.0056712
30	2.3168	2.3635	2.3958	0.028316	2.3044	2.3684	2.4045	0.03232	-0.0687	0.00485	0.0235	0.027374
50	2.3208	2.3584	2.3982	0.026985	2.3401	2.3815	2.4226	0.029294	0.0004	0.02311	0.0396	0.013721

Device Test: 23.12 LEVEL|LS_RDSON/OUTL/14/14/100/0/5/500kHz//@ROL





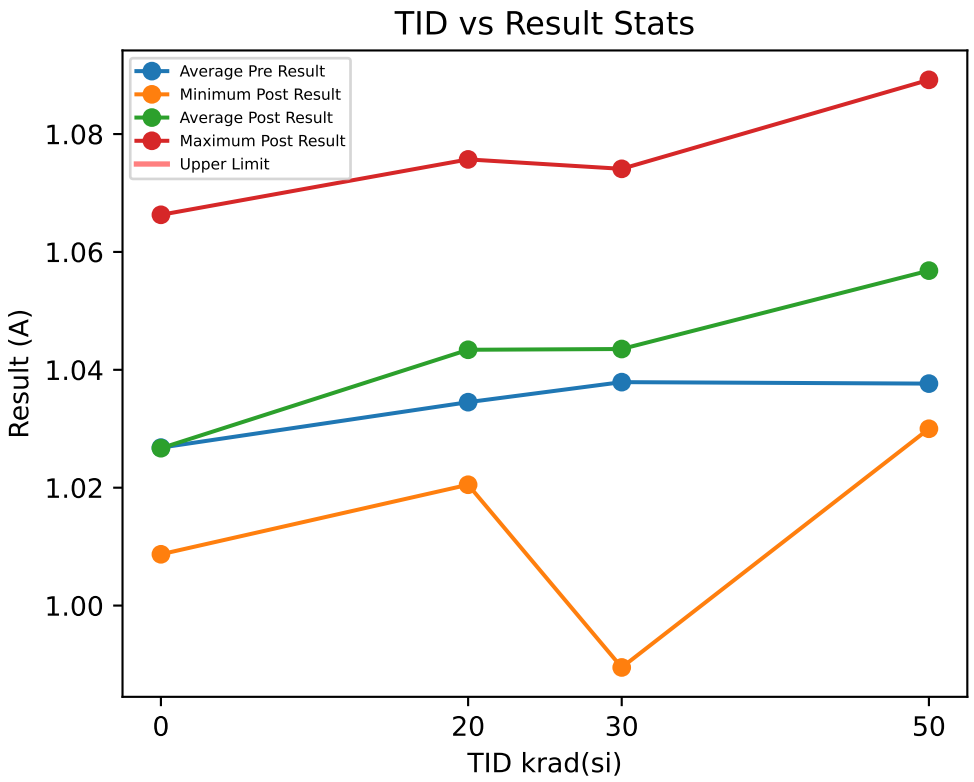
Test Results (Upper Limit = 2.8 (Ω))

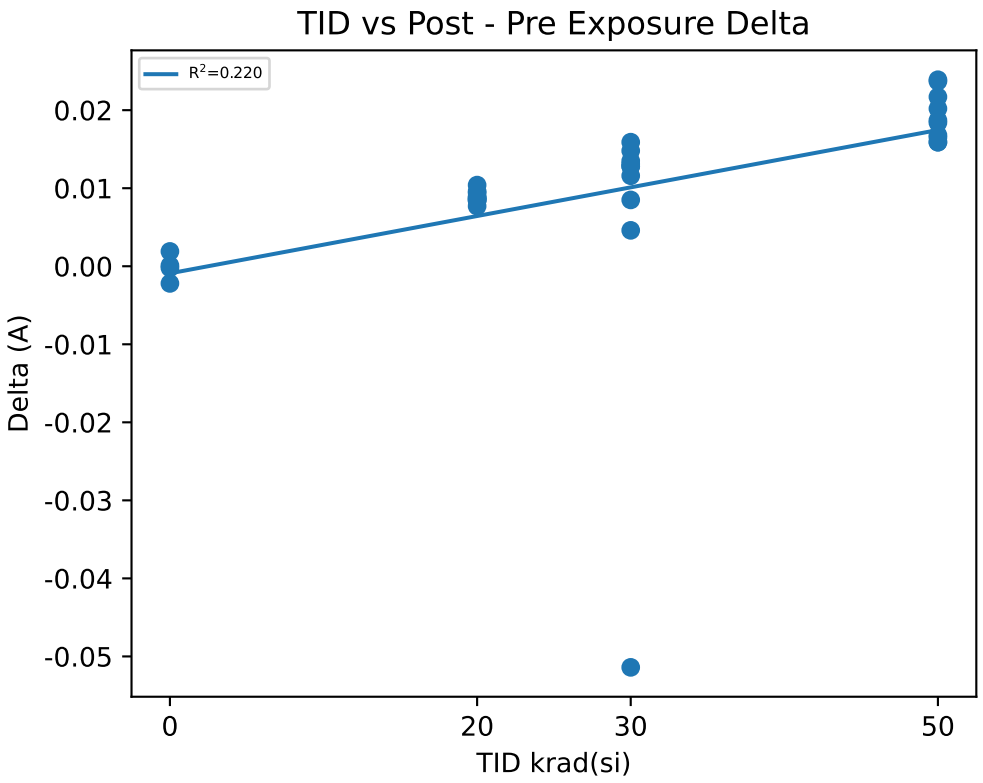
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	1.6004	1.5459	-0.0545
2	20	Unbiased	1.6058	1.5945	-0.0113
3	50	Biased	1.6037	1.5563	-0.0474
4	30	Unbiased	1.6085	1.5898	-0.0187
5	50	Unbiased	1.6162	1.5938	-0.0224
6	30	Biased	1.6183	1.5726	-0.0457
7	50	Biased	1.6188	1.5618	-0.057
8	30	Unbiased	1.6051	1.5969	-0.0082
9	20	Unbiased	1.6178	1.5994	-0.0184
10	50	Biased	1.6236	1.5653	-0.0583
11	30	Biased	1.6039	1.5467	-0.0572
12	0	Correlation	1.6245	1.6185	-0.006
13	0	Correlation	1.6242	1.6222	-0.002
14	50	Unbiased	1.6164	1.5952	-0.0212
15	20	Biased	1.6134	1.569	-0.0444
16	20	Unbiased	1.6265	1.612	-0.0145
17	20	Biased	1.6286	1.5887	-0.0399
18	20	Unbiased	1.6305	1.6137	-0.0168
19	20	Biased	1.6115	1.5653	-0.0462
20	50	Unbiased	1.626	1.5996	-0.0264
21	0	Correlation	1.6092	1.6084	-0.0008
22	50	Unbiased	1.6173	1.5907	-0.0266
23	0	Correlation	1.6258	1.6261	0.0003
24	20	Biased	1.6298	1.5872	-0.0426
26	50	Biased	1.62	1.5667	-0.0533
27	30	Unbiased	1.6178	1.6065	-0.0113
28	30	Biased	1.6262	1.5591	-0.0671
29	30	Unbiased	1.6012	1.5812	-0.02
30	20	Biased	1.6226	1.5698	-0.0528
31	30	Unbiased	1.6179	1.613	-0.0049
33	30	Biased	1.6358	1.569	-0.0668
34	50	Unbiased	1.6076	1.5857	-0.0219
35	20	Unbiased	1.6045	1.584	-0.0205
41	30	Biased	1.6094	1.5677	-0.0417

Test Statistics (Ω)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.6092	1.6209	1.6258	0.0078475	1.6084	1.6188	1.6261	0.0075961	-0.006	-0.002125	0.0003	0.0027488
20	1.6045	1.6191	1.6305	0.009909	1.5653	1.5884	1.6137	0.017101	-0.0528	-0.03074	-0.0113	0.015741
30	1.6012	1.6144	1.6358	0.010888	1.5467	1.5802	1.613	0.021204	-0.0671	-0.03416	-0.0049	0.024412
50	1.6004	1.615	1.626	0.0084242	1.5459	1.5761	1.5996	0.019001	-0.0583	-0.0389	-0.0212	0.016361

Device Test: 23.2 CURRENT|SINK/OUTL/4.5/4.5/0/0/4.5/500kHz//@OUT_IOL_4P5V





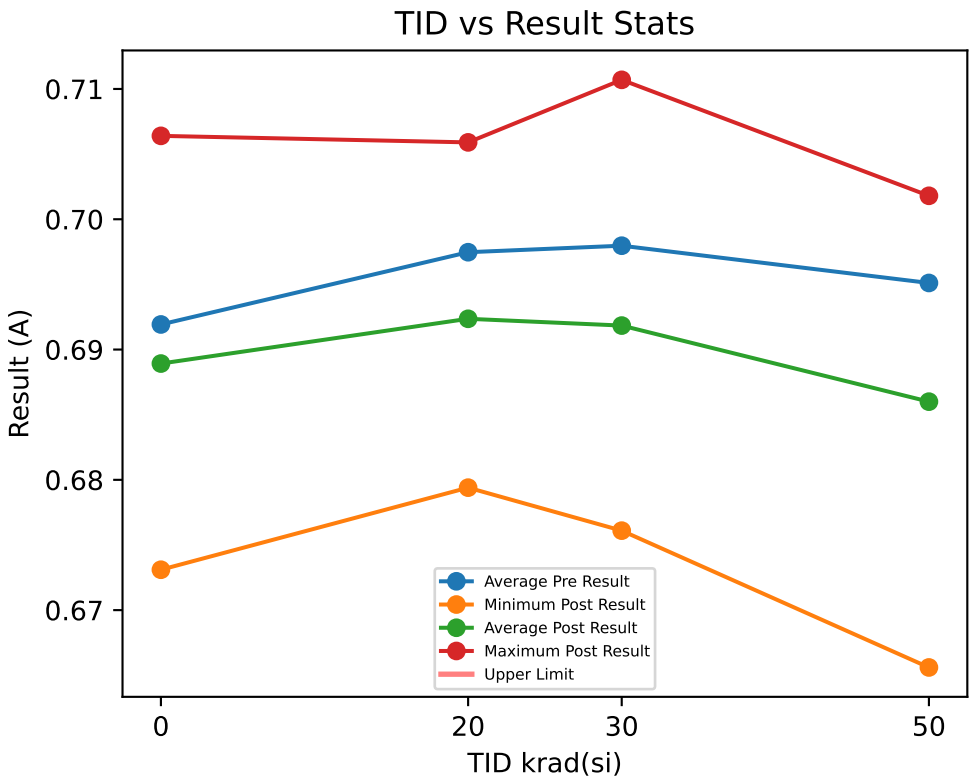
Test Results (No Limits Specified (A))

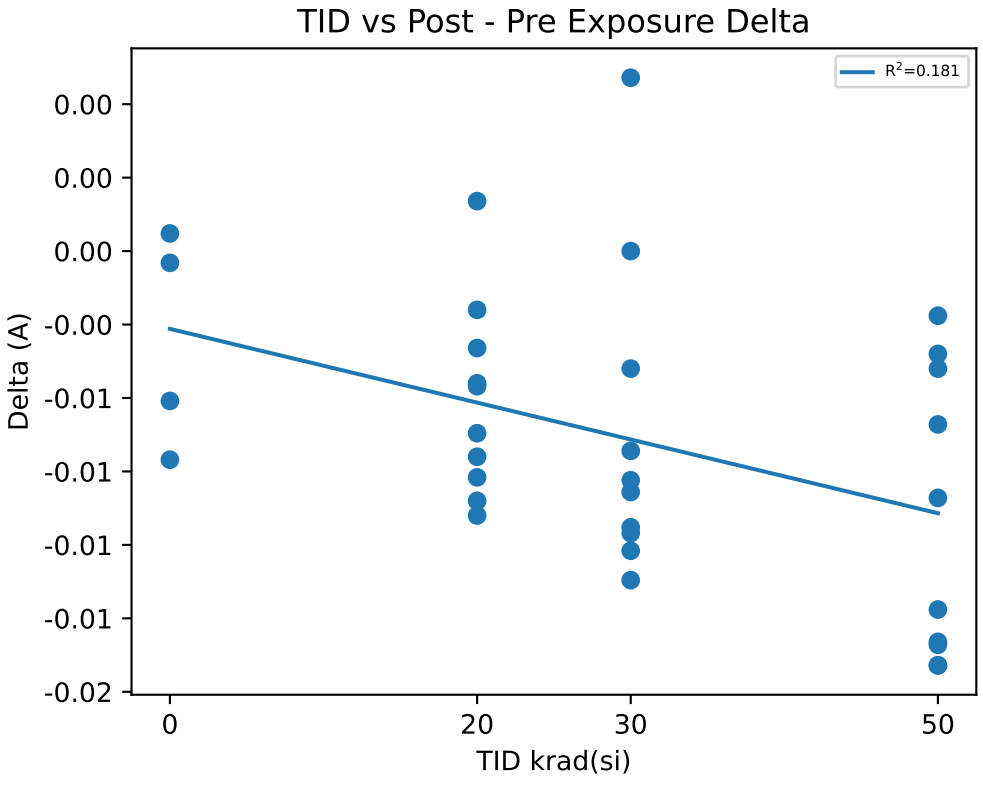
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	1.0428	1.0587	0.0159
2	20	Unbiased	1.0562	1.0651	0.0089
3	50	Biased	1.0669	1.0856	0.0187
4	30	Unbiased	1.0606	1.0741	0.0135
5	50	Unbiased	1.0487	1.0671	0.0184
6	30	Biased	1.0238	1.0323	0.0085
7	50	Biased	1.0203	1.0362	0.0159
8	30	Unbiased	1.046	1.0588	0.0128
9	20	Unbiased	1.0531	1.0618	0.0087
10	50	Biased	1.0163	1.0331	0.0168
11	30	Biased	1.0535	1.0663	0.0128
12	0	Correlation	1.0227	1.0205	-0.0022
13	0	Correlation	1.0112	1.0113	0.0001
14	50	Unbiased	1.0341	1.0543	0.0202
15	20	Biased	1.0357	1.0441	0.0084
16	20	Unbiased	1.0117	1.0205	0.0088
17	20	Biased	1.0187	1.0272	0.0085
18	20	Unbiased	1.0167	1.0261	0.0094
19	20	Biased	1.0578	1.0682	0.0104
20	50	Unbiased	1.0235	1.0452	0.0217
21	0	Correlation	1.0665	1.0663	-0.0002
22	50	Unbiased	1.0452	1.0689	0.0237
23	0	Correlation	1.0068	1.0087	0.0019
24	20	Biased	1.0132	1.0209	0.0077
26	50	Biased	1.0135	1.03	0.0165
27	30	Unbiased	1.0155	1.0314	0.0159
28	30	Biased	1.0215	1.0346	0.0131
29	30	Unbiased	1.059	1.0738	0.0148
30	20	Biased	1.0159	1.0244	0.0085
31	30	Unbiased	1.0258	1.0304	0.0046
33	30	Biased	1.0325	1.0441	0.0116
34	50	Unbiased	1.0653	1.0892	0.0239
35	20	Unbiased	1.0661	1.0757	0.0096
41	30	Biased	1.0409	0.9895	-0.0514

Test Statistics (A)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.0068	1.0268	1.0665	0.027302	1.0087	1.0267	1.0663	0.026881	-0.0022	-0.0001	0.0019	0.0016793
20	1.0117	1.0345	1.0661	0.02172	1.0205	1.0434	1.0757	0.022165	0.0077	0.00889	0.0104	0.000749
30	1.0155	1.0379	1.0606	0.01641	0.9895	1.0435	1.0741	0.025922	-0.0514	0.00562	0.0159	0.020296
50	1.0135	1.0377	1.0669	0.019375	1.03	1.0568	1.0892	0.02103	0.0159	0.01917	0.0239	0.0030786

Device Test: 23.3 CURRENT|SOURCE/OUTH/5/5/0/0/5/500kHz//@OUT_IOH_5V





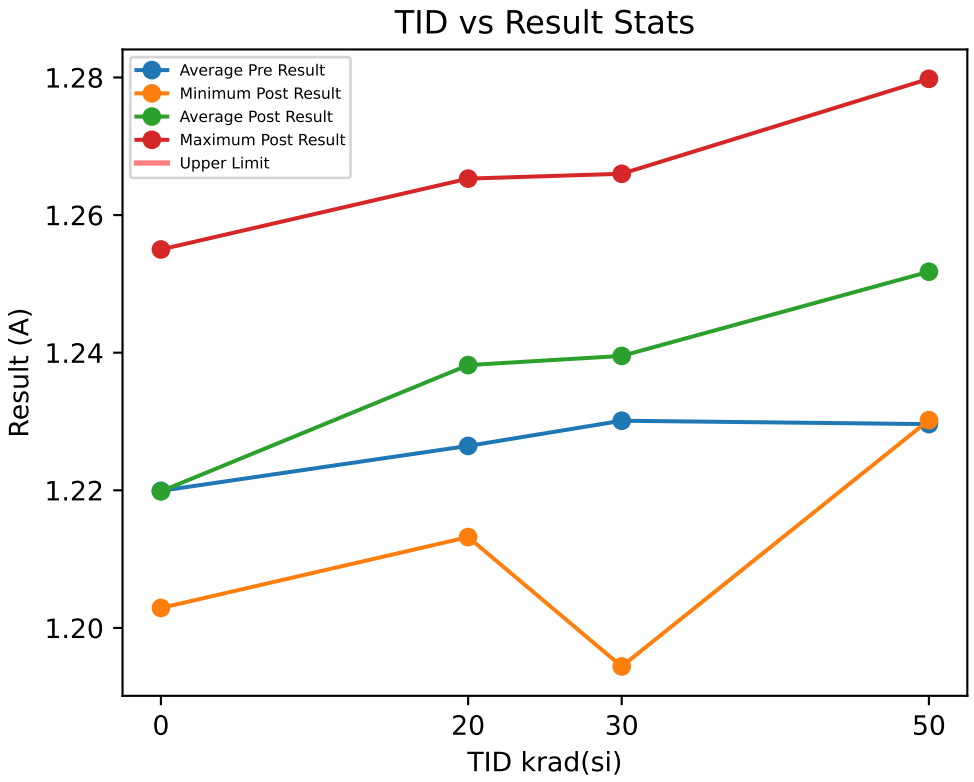
Test Results (No Limits Specified (A))

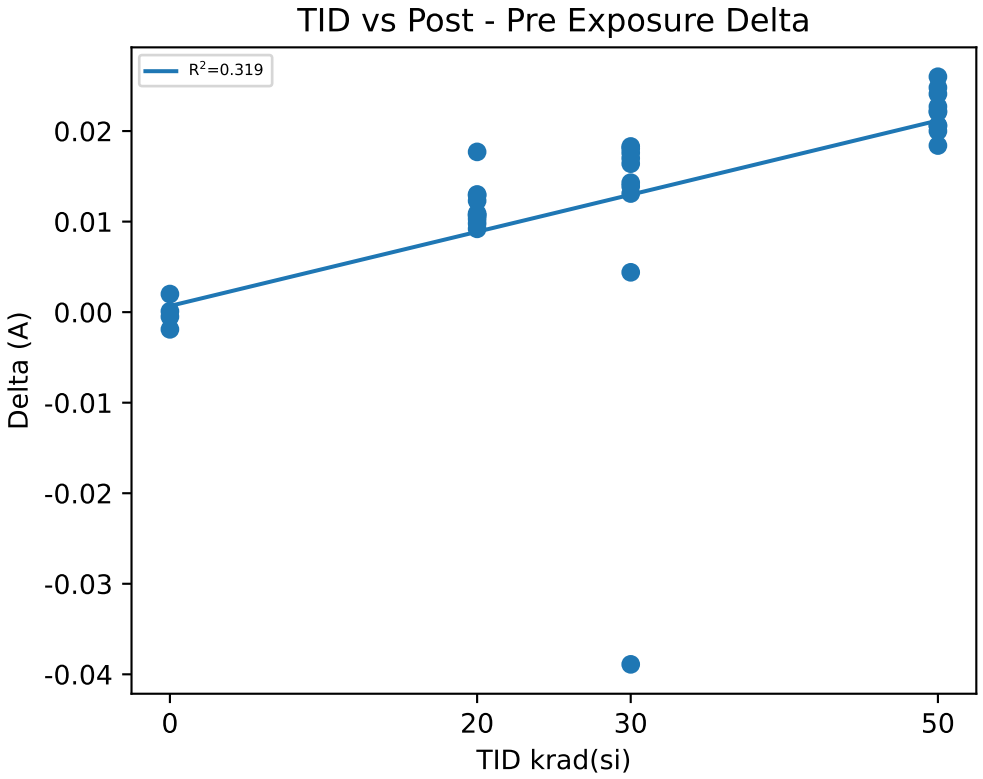
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	0.7152	0.7018	-0.0134
2	20	Unbiased	0.7071	0.7026	-0.0045
3	50	Biased	0.7116	0.6975	-0.0141
4	30	Unbiased	0.7209	0.7107	-0.0102
5	50	Unbiased	0.686	0.6719	-0.0141
6	30	Biased	0.6854	0.6814	-0.004
7	50	Biased	0.6792	0.6659	-0.0133
8	30	Unbiased	0.7142	0.706	-0.0082
9	20	Unbiased	0.7105	0.7059	-0.0046
10	50	Biased	0.7071	0.7012	-0.0059
11	30	Biased	0.7076	0.698	-0.0096
12	0	Correlation	0.6802	0.6731	-0.0071
13	0	Correlation	0.6915	0.6864	-0.0051
14	50	Unbiased	0.6925	0.6885	-0.004
15	20	Biased	0.6871	0.6794	-0.0077
16	20	Unbiased	0.6988	0.6918	-0.007
17	20	Biased	0.6919	0.6886	-0.0033
18	20	Unbiased	0.6818	0.6835	0.0017
19	20	Biased	0.712	0.703	-0.009
20	50	Unbiased	0.6778	0.6656	-0.0122
21	0	Correlation	0.7058	0.7064	0.0006
22	50	Unbiased	0.694	0.6905	-0.0035
23	0	Correlation	0.6902	0.6898	-0.0004
24	20	Biased	0.6897	0.6835	-0.0062
26	50	Biased	0.6806	0.6784	-0.0022
27	30	Unbiased	0.6882	0.6814	-0.0068
28	30	Biased	0.6873	0.6761	-0.0112
29	30	Unbiased	0.7081	0.6987	-0.0094
30	20	Biased	0.6834	0.6814	-0.002
31	30	Unbiased	0.6902	0.6902	0
33	30	Biased	0.6904	0.6826	-0.0078
34	50	Unbiased	0.7071	0.6987	-0.0084
35	20	Unbiased	0.7124	0.7039	-0.0085
41	30	Biased	0.6874	0.6933	0.0059

Test Statistics (A)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.6802	0.69193	0.7058	0.010538	0.6731	0.68893	0.7064	0.013699	-0.0071	-0.003	0.0006	0.0036941
20	0.6818	0.69747	0.7124	0.012205	0.6794	0.69236	0.7059	0.01051	-0.009	-0.00511	0.0017	0.0033007
30	0.6854	0.69797	0.7209	0.013255	0.6761	0.69184	0.7107	0.011533	-0.0112	-0.00613	0.0059	0.0053682
50	0.6778	0.69511	0.7152	0.01421	0.6656	0.686	0.7018	0.014443	-0.0141	-0.00911	-0.0022	0.0048471

Device Test: 23.4 CURRENT|SINK/OUTL/5/5/0/0/5/500kHz//@OUT_IOL_5V





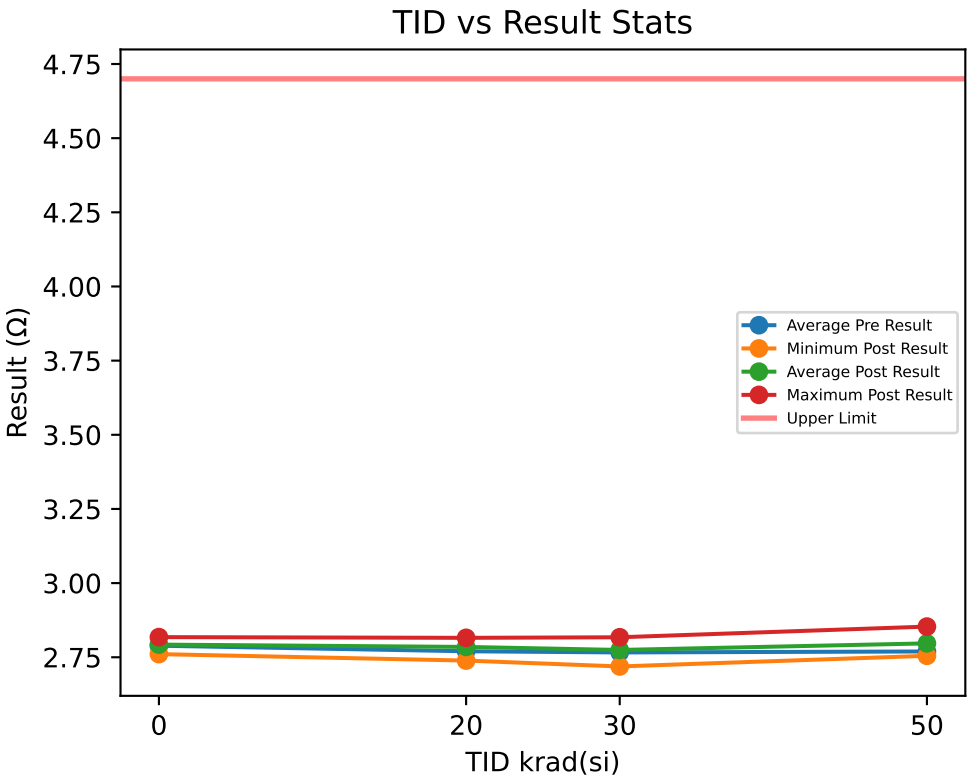
Test Results (No Limits Specified (A))

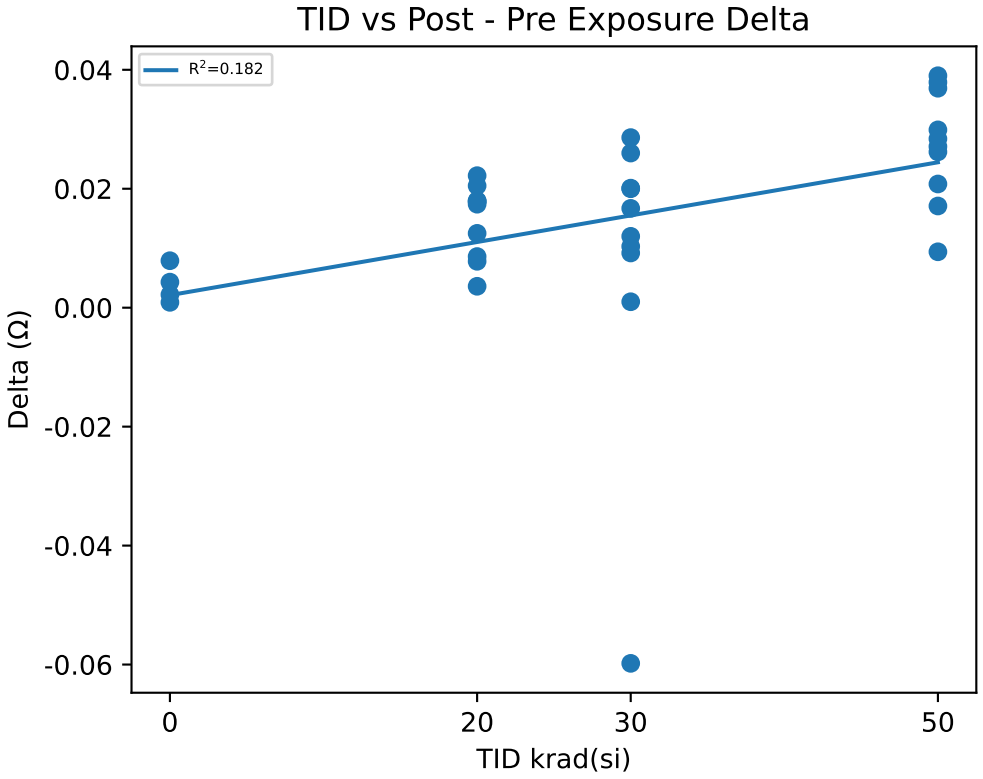
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	1.235	1.2577	0.0227
2	20	Unbiased	1.2464	1.2573	0.0109
3	50	Biased	1.2538	1.2798	0.026
4	30	Unbiased	1.251	1.2653	0.0143
5	50	Unbiased	1.2378	1.2562	0.0184
6	30	Biased	1.2167	1.2298	0.0131
7	50	Biased	1.2159	1.2359	0.02
8	30	Unbiased	1.2376	1.2515	0.0139
9	20	Unbiased	1.2421	1.2519	0.0098
10	50	Biased	1.21	1.2321	0.0221
11	30	Biased	1.2451	1.2634	0.0183
12	0	Correlation	1.2171	1.2152	-0.0019
13	0	Correlation	1.2062	1.2063	0.0001
14	50	Unbiased	1.227	1.2476	0.0206
15	20	Biased	1.2278	1.2408	0.013
16	20	Unbiased	1.204	1.2132	0.0092
17	20	Biased	1.2117	1.2246	0.0129
18	20	Unbiased	1.2096	1.2199	0.0103
19	20	Biased	1.2471	1.2648	0.0177
20	50	Unbiased	1.2163	1.2385	0.0222
21	0	Correlation	1.2555	1.255	-0.0005
22	50	Unbiased	1.2369	1.261	0.0241
23	0	Correlation	1.2009	1.2029	0.002
24	20	Biased	1.2096	1.2203	0.0107
26	50	Biased	1.2096	1.2302	0.0206
27	30	Unbiased	1.2096	1.2266	0.017
28	30	Biased	1.2163	1.2344	0.0181
29	30	Unbiased	1.2496	1.266	0.0164
30	20	Biased	1.2116	1.2239	0.0123
31	30	Unbiased	1.2187	1.2231	0.0044
33	30	Biased	1.2232	1.2408	0.0176
34	50	Unbiased	1.2539	1.2787	0.0248
35	20	Unbiased	1.2546	1.2653	0.0107
41	30	Biased	1.2333	1.1944	-0.0389

Test Statistics (A)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2009	1.2199	1.2555	0.024657	1.2029	1.2199	1.255	0.024	-0.0019	-7.5e-05	0.002	0.0016174
20	1.204	1.2265	1.2546	0.019361	1.2132	1.2382	1.2653	0.020196	0.0092	0.01175	0.0177	0.0024478
30	1.2096	1.2301	1.251	0.015189	1.1944	1.2395	1.266	0.02279	-0.0389	0.00942	0.0183	0.017463
50	1.2096	1.2296	1.2539	0.016604	1.2302	1.2518	1.2798	0.0181	0.0184	0.02215	0.026	0.0023439

Device Test: 23.5 LEVEL|HS_RDSON/OUTH/4.5/4.5/100/0/4.5/500kHz//@ROH





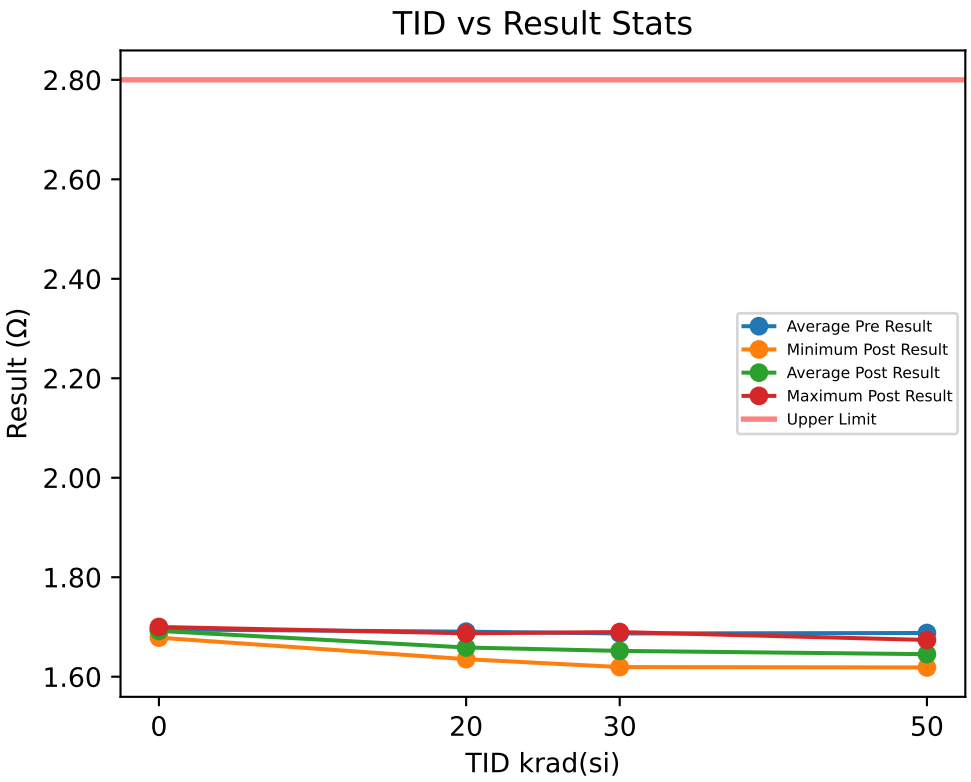
Test Results (Upper Limit = 4.7 (Ω))

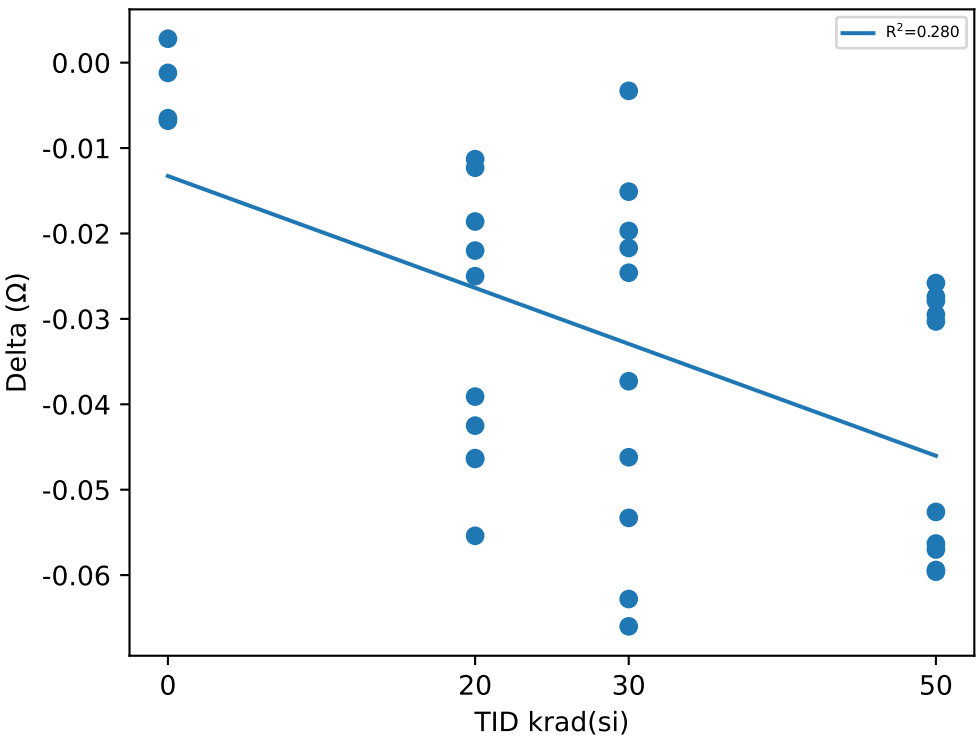
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	2.7242	2.7611	0.0369
2	20	Unbiased	2.7327	2.7507	0.018
3	50	Biased	2.7281	2.7671	0.039
4	30	Unbiased	2.7144	2.7404	0.026
5	50	Unbiased	2.8015	2.8286	0.0271
6	30	Biased	2.7947	2.8114	0.0167
7	50	Biased	2.8078	2.8457	0.0379
8	30	Unbiased	2.7221	2.7507	0.0286
9	20	Unbiased	2.7468	2.7593	0.0125
10	50	Biased	2.7385	2.7669	0.0284
11	30	Biased	2.7357	2.7558	0.0201
12	0	Correlation	2.81	2.8179	0.0079
13	0	Correlation	2.7991	2.8	0.0009
14	50	Unbiased	2.7663	2.7834	0.0171
15	20	Biased	2.7931	2.811	0.0179
16	20	Unbiased	2.7785	2.8007	0.0222
17	20	Biased	2.7913	2.8091	0.0178
18	20	Unbiased	2.8069	2.8155	0.0086
19	20	Biased	2.7324	2.7529	0.0205
20	50	Unbiased	2.8235	2.8534	0.0299
21	0	Correlation	2.7563	2.7606	0.0043
22	50	Unbiased	2.7681	2.7775	0.0094
23	0	Correlation	2.7902	2.7924	0.0022
24	20	Biased	2.7924	2.8098	0.0174
26	50	Biased	2.8032	2.8294	0.0262
27	30	Unbiased	2.7984	2.8087	0.0103
28	30	Biased	2.7974	2.8174	0.02
29	30	Unbiased	2.7399	2.7491	0.0092
30	20	Biased	2.7969	2.8005	0.0036
31	30	Unbiased	2.7892	2.7902	0.001
33	30	Biased	2.7917	2.8037	0.012
34	50	Unbiased	2.7341	2.7549	0.0208
35	20	Unbiased	2.731	2.7388	0.0078
41	30	Biased	2.7788	2.719	-0.0598

Test Statistics (Ω)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.7563	2.7889	2.81	0.023193	2.7606	2.7927	2.8179	0.023936	0.0009	0.003825	0.0079	0.0030566
20	2.731	2.7702	2.8069	0.030751	2.7388	2.7848	2.8155	0.030351	0.0036	0.01463	0.0222	0.0061531
30	2.7144	2.7662	2.7984	0.034011	2.719	2.7746	2.8174	0.035395	-0.0598	0.00841	0.0286	0.025345
50	2.7242	2.7695	2.8235	0.03732	2.7549	2.7968	2.8534	0.038045	0.0094	0.02727	0.039	0.0095296

Device Test: 23.6 LEVEL|LS_RDSON/OUTL/4.5/4.5/100/0/4.5/500kHz//@ROL





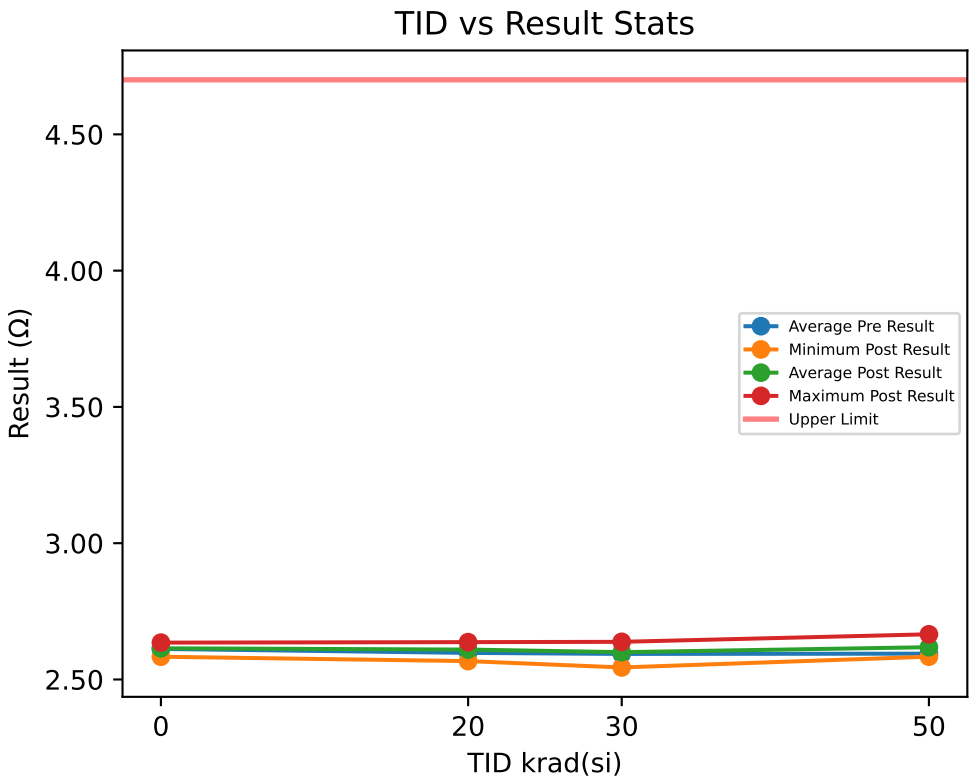
Test Results (Upper Limit = 2.8 (Ω))

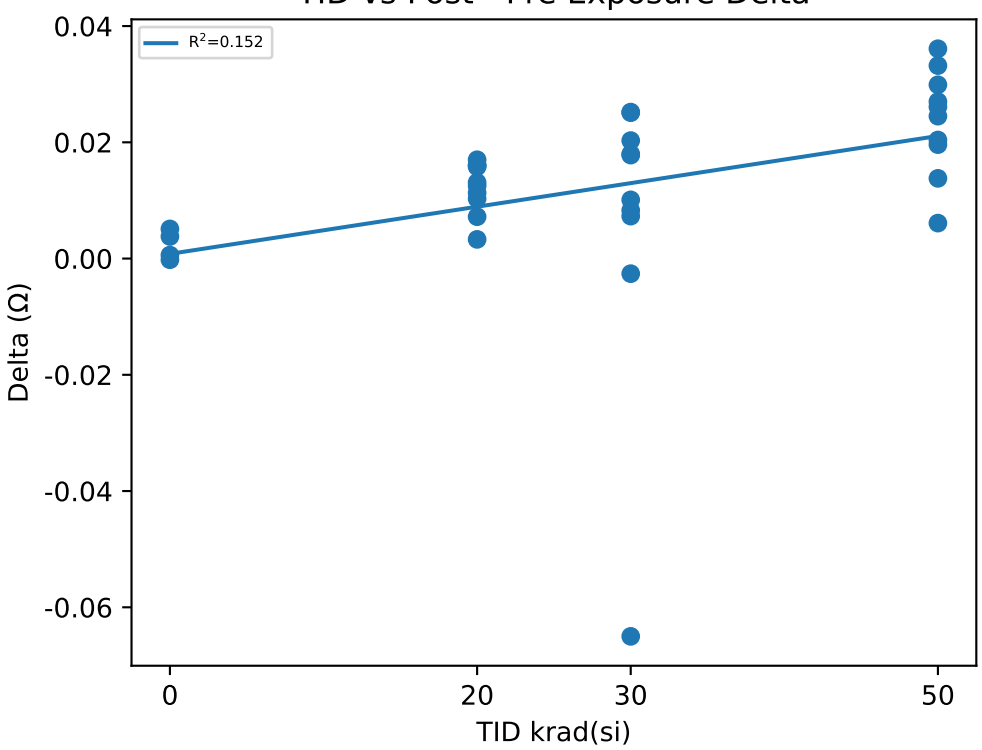
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	1.6756	1.6186	-0.057
2	20	Unbiased	1.6759	1.6646	-0.0113
3	50	Biased	1.6765	1.6239	-0.0526
4	30	Unbiased	1.6759	1.6562	-0.0197
5	50	Unbiased	1.6852	1.6594	-0.0258
6	30	Biased	1.6898	1.6436	-0.0462
7	50	Biased	1.6948	1.6352	-0.0596
8	30	Unbiased	1.6802	1.6651	-0.0151
9	20	Unbiased	1.6854	1.6668	-0.0186
10	50	Biased	1.6925	1.6362	-0.0563
11	30	Biased	1.6727	1.6194	-0.0533
12	0	Correlation	1.6979	1.6911	-0.0068
13	0	Correlation	1.7012	1.7	-0.0012
14	50	Unbiased	1.6881	1.6607	-0.0274
15	20	Biased	1.6844	1.6381	-0.0463
16	20	Unbiased	1.703	1.681	-0.022
17	20	Biased	1.6996	1.6605	-0.0391
18	20	Unbiased	1.6995	1.6872	-0.0123
19	20	Biased	1.6817	1.6353	-0.0464
20	50	Unbiased	1.7034	1.6739	-0.0295
21	0	Correlation	1.6757	1.6785	0.0028
22	50	Unbiased	1.6865	1.6562	-0.0303
23	0	Correlation	1.7054	1.6989	-0.0065
24	20	Biased	1.7022	1.6597	-0.0425
26	50	Biased	1.6945	1.6351	-0.0594
27	30	Unbiased	1.6958	1.6712	-0.0246
28	30	Biased	1.699	1.6362	-0.0628
29	30	Unbiased	1.673	1.6513	-0.0217
30	20	Biased	1.6961	1.6407	-0.0554
31	30	Unbiased	1.6931	1.6898	-0.0033
33	30	Biased	1.7094	1.6434	-0.066
34	50	Unbiased	1.6819	1.654	-0.0279
35	20	Unbiased	1.6781	1.6531	-0.025
41	30	Biased	1.6802	1.6429	-0.0373

Test Statistics (Ω)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.6757	1.695	1.7054	0.01326	1.6785	1.6921	1.7	0.0099097	-0.0068	-0.002925	0.0028	0.0046024
20	1.6759	1.6906	1.703	0.010519	1.6353	1.6587	1.6872	0.017453	-0.0554	-0.03189	-0.0113	0.015864
30	1.6727	1.6869	1.7094	0.012402	1.6194	1.6519	1.6898	0.019796	-0.066	-0.035	-0.0033	0.021394
50	1.6756	1.6879	1.7034	0.0086866	1.6186	1.6453	1.6739	0.017976	-0.0596	-0.04258	-0.0258	0.015343

Device Test: 23.7 LEVEL|HS_RDSON/OUTH/5/5/100/0/5/500kHz//@ROH





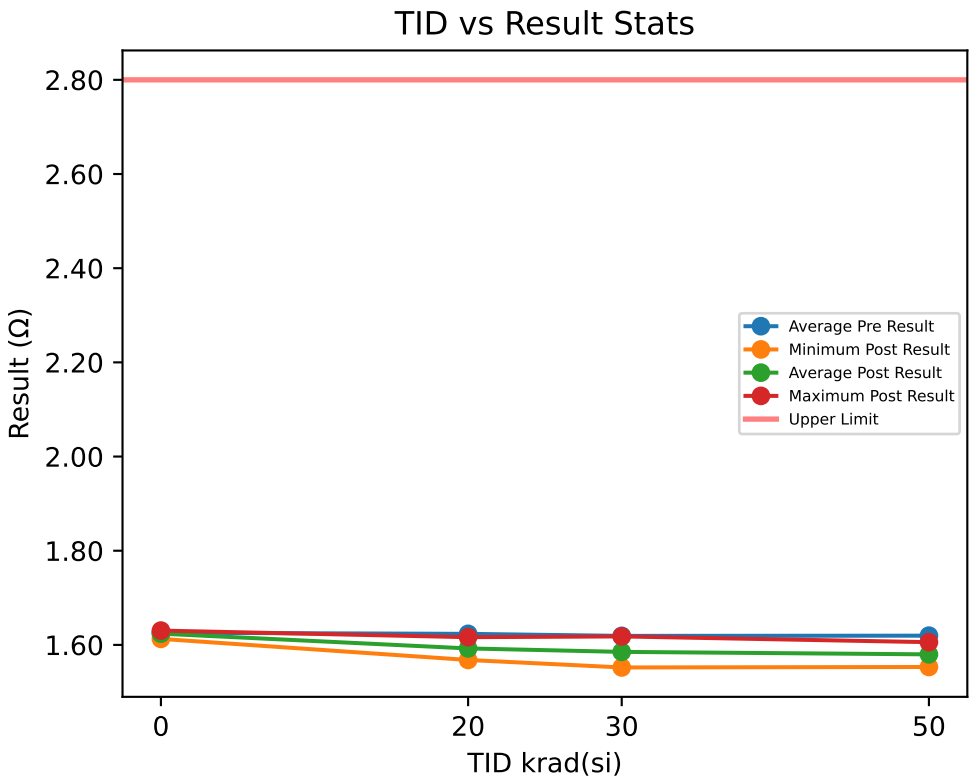
Test Results (Upper Limit = 4.7 (Ω))

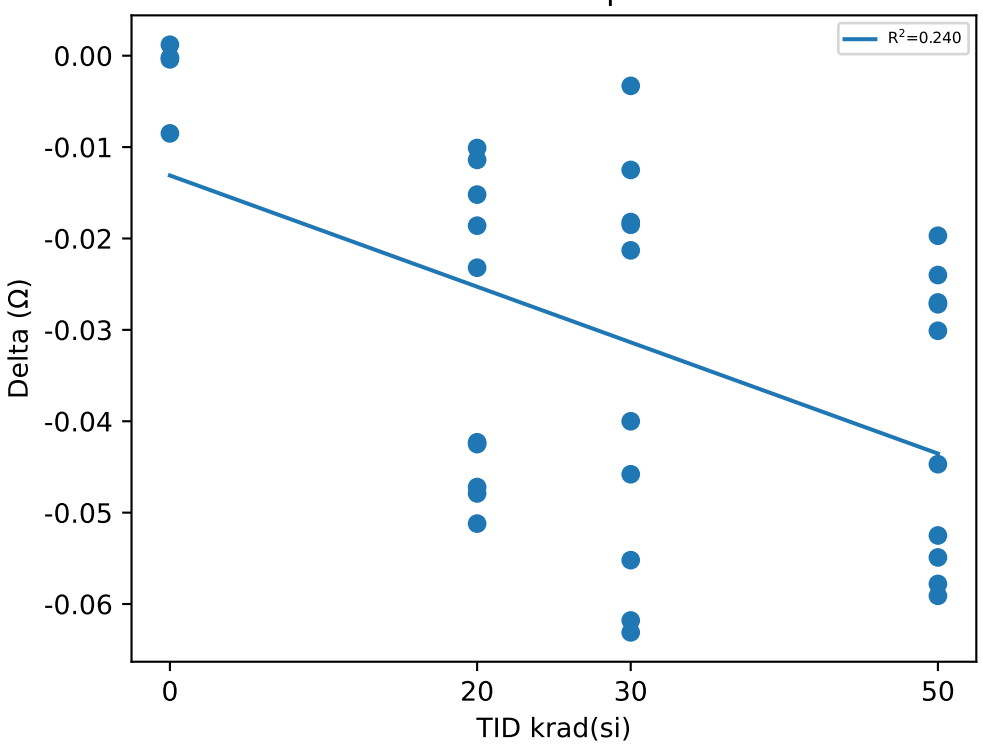
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	2.5545	2.5844	0.0299
2	20	Unbiased	2.5651	2.5782	0.0131
3	50	Biased	2.5603	2.5935	0.0332
4	30	Unbiased	2.5471	2.5723	0.0252
5	50	Unbiased	2.6214	2.6475	0.0261
6	30	Biased	2.615	2.6328	0.0178
7	50	Biased	2.6275	2.6636	0.0361
8	30	Unbiased	2.5545	2.5796	0.0251
9	20	Unbiased	2.5793	2.5896	0.0103
10	50	Biased	2.5692	2.5962	0.027
11	30	Biased	2.5646	2.5849	0.0203
12	0	Correlation	2.6301	2.6352	0.0051
13	0	Correlation	2.6213	2.6251	0.0038
14	50	Unbiased	2.5911	2.6049	0.0138
15	20	Biased	2.6173	2.6298	0.0125
16	20	Unbiased	2.6069	2.6227	0.0158
17	20	Biased	2.6159	2.632	0.0161
18	20	Unbiased	2.6257	2.637	0.0113
19	20	Biased	2.5658	2.5828	0.017
20	50	Unbiased	2.6413	2.6658	0.0245
21	0	Correlation	2.5837	2.5835	-0.0002
22	50	Unbiased	2.5925	2.5986	0.0061
23	0	Correlation	2.6133	2.6139	0.0006
24	20	Biased	2.6179	2.6339	0.016
26	50	Biased	2.626	2.6456	0.0196
27	30	Unbiased	2.6222	2.6295	0.0073
28	30	Biased	2.6201	2.6381	0.018
29	30	Unbiased	2.5703	2.5786	0.0083
30	20	Biased	2.6169	2.6241	0.0072
31	30	Unbiased	2.6182	2.6156	-0.0026
33	30	Biased	2.6163	2.6264	0.0101
34	50	Unbiased	2.5632	2.5836	0.0204
35	20	Unbiased	2.5641	2.5674	0.0033
41	30	Biased	2.6091	2.5441	-0.065

Test Statistics (Ω)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.5837	2.6121	2.6301	0.020138	2.5835	2.6144	2.6352	0.022377	-0.0002	0.002325	0.0051	0.0025316
20	2.5641	2.5975	2.6257	0.025622	2.5674	2.6098	2.637	0.026911	0.0033	0.01226	0.017	0.0044114
30	2.5471	2.5937	2.6222	0.030575	2.5441	2.6002	2.6381	0.032201	-0.065	0.00645	0.0252	0.026579
50	2.5545	2.5947	2.6413	0.032317	2.5836	2.6184	2.6658	0.033218	0.0061	0.02367	0.0361	0.0090382

Device Test: 23.8 LEVEL|LS_RDSON/OUTL/5/5/100/0/5/500kHz//@ROL





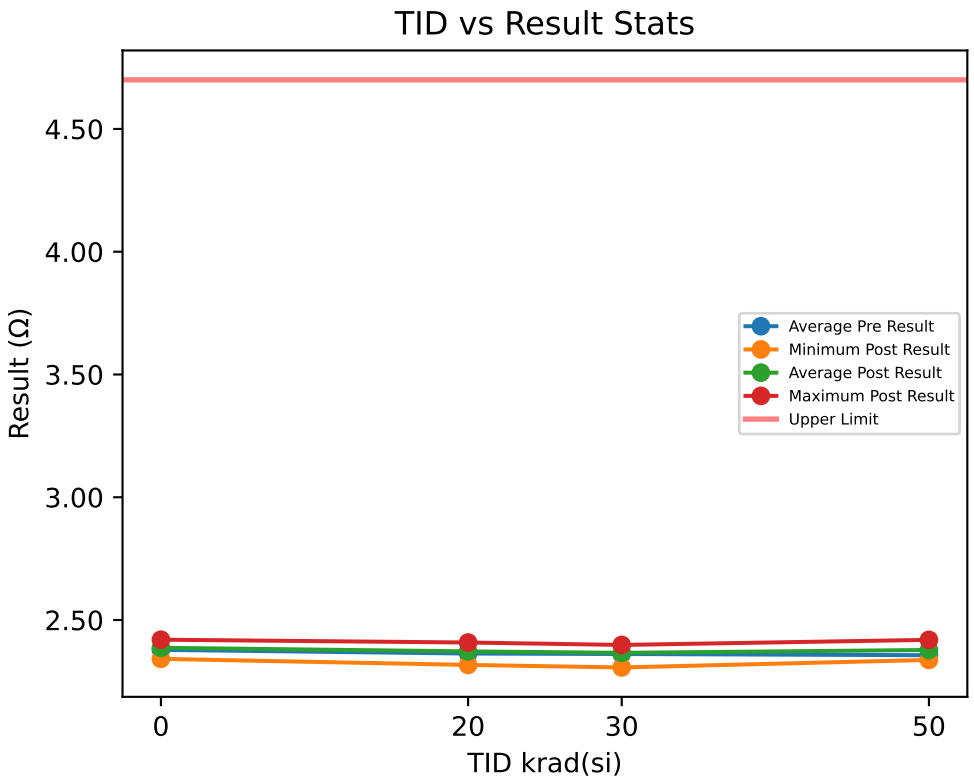
Test Results (Upper Limit = 2.8 (Ω))

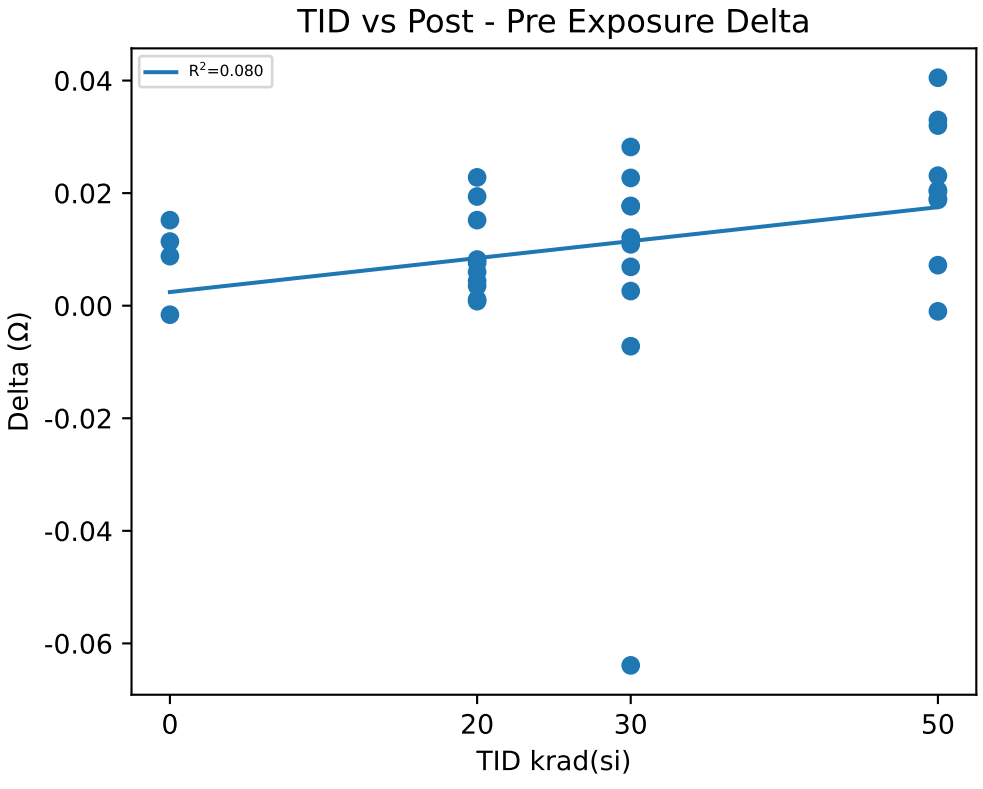
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	1.6056	1.5531	-0.0525
2	20	Unbiased	1.6092	1.5991	-0.0101
3	50	Biased	1.6083	1.5636	-0.0447
4	30	Unbiased	1.6155	1.5942	-0.0213
5	50	Unbiased	1.6171	1.5974	-0.0197
6	30	Biased	1.6227	1.5769	-0.0458
7	50	Biased	1.6241	1.5663	-0.0578
8	30	Unbiased	1.6104	1.5979	-0.0125
9	20	Unbiased	1.6179	1.6065	-0.0114
10	50	Biased	1.6253	1.5662	-0.0591
11	30	Biased	1.6073	1.5521	-0.0552
12	0	Correlation	1.6306	1.6221	-0.0085
13	0	Correlation	1.6304	1.6302	-0.0002
14	50	Unbiased	1.6218	1.5978	-0.024
15	20	Biased	1.6187	1.5708	-0.0479
16	20	Unbiased	1.6341	1.6155	-0.0186
17	20	Biased	1.634	1.5915	-0.0425
18	20	Unbiased	1.6316	1.6164	-0.0152
19	20	Biased	1.6152	1.568	-0.0472
20	50	Unbiased	1.6359	1.6058	-0.0301
21	0	Correlation	1.6116	1.6128	0.0012
22	50	Unbiased	1.6192	1.5922	-0.027
23	0	Correlation	1.6308	1.6304	-0.0004
24	20	Biased	1.634	1.5917	-0.0423
26	50	Biased	1.6243	1.5694	-0.0549
27	30	Unbiased	1.6241	1.6056	-0.0185
28	30	Biased	1.6289	1.5671	-0.0618
29	30	Unbiased	1.6056	1.5874	-0.0182
30	20	Biased	1.6265	1.5753	-0.0512
31	30	Unbiased	1.6213	1.618	-0.0033
33	30	Biased	1.6393	1.5762	-0.0631
34	50	Unbiased	1.6146	1.5874	-0.0272
35	20	Unbiased	1.6135	1.5903	-0.0232
41	30	Biased	1.6164	1.5764	-0.04

Test Statistics (Ω)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.6116	1.6259	1.6308	0.0095014	1.6128	1.6239	1.6304	0.0083344	-0.0085	-0.001975	0.0012	0.0044079
20	1.6092	1.6235	1.6341	0.0096335	1.568	1.5925	1.6164	0.017363	-0.0512	-0.03096	-0.0101	0.016671
30	1.6056	1.6192	1.6393	0.010351	1.5521	1.5852	1.618	0.019407	-0.0631	-0.03397	-0.0033	0.021859
50	1.6056	1.6196	1.6359	0.008822	1.5531	1.5799	1.6058	0.018172	-0.0591	-0.0397	-0.0197	0.015564

Device Test: 23.9 LEVEL|HS_RDSON/OUTH/12/12/100/0/5/500kHz//@ROH





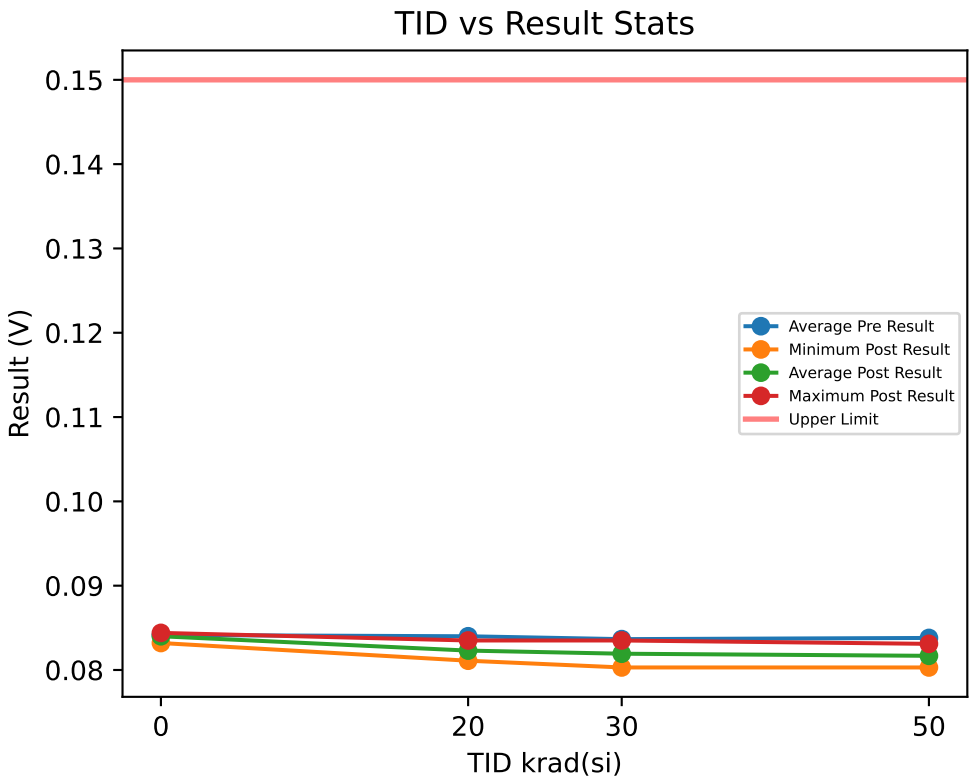
Test Results (Upper Limit = 4.7 (Ω))

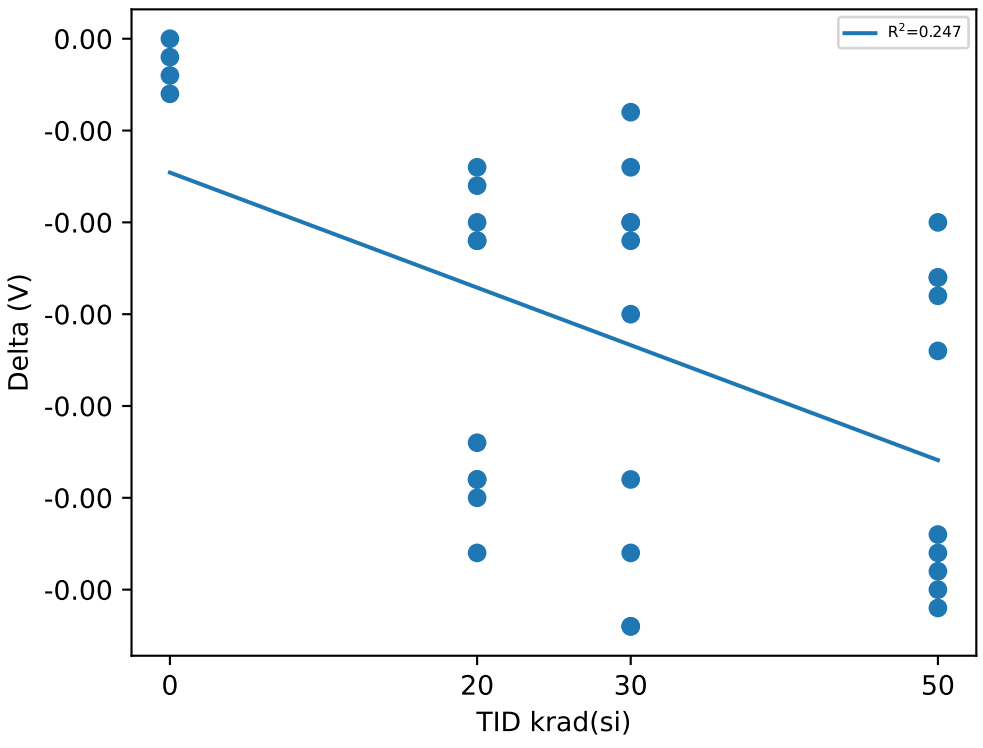
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	2.3226	2.3556	0.033
2	20	Unbiased	2.3266	2.3418	0.0152
3	50	Biased	2.3322	2.3727	0.0405
4	30	Unbiased	2.3113	2.329	0.0177
5	50	Unbiased	2.3822	2.4012	0.019
6	30	Biased	2.3798	2.3907	0.0109
7	50	Biased	2.3824	2.4144	0.032
8	30	Unbiased	2.3136	2.3418	0.0282
9	20	Unbiased	2.3583	2.3665	0.0082
10	50	Biased	2.3507	2.3712	0.0205
11	30	Biased	2.3463	2.364	0.0177
12	0	Correlation	2.4084	2.4198	0.0114
13	0	Correlation	2.3882	2.4034	0.0152
14	50	Unbiased	2.3584	2.3574	-0.001
15	20	Biased	2.4049	2.4084	0.0035
16	20	Unbiased	2.3578	2.3772	0.0194
17	20	Biased	2.3927	2.3987	0.006
18	20	Unbiased	2.3887	2.3931	0.0044
19	20	Biased	2.3348	2.3576	0.0228
20	50	Unbiased	2.3961	2.4192	0.0231
21	0	Correlation	2.3434	2.3418	-0.0016
22	50	Unbiased	2.3459	2.3531	0.0072
23	0	Correlation	2.3738	2.3826	0.0088
24	20	Biased	2.3836	2.3912	0.0076
26	50	Biased	2.3772	2.3975	0.0203
27	30	Unbiased	2.3967	2.3895	-0.0072
28	30	Biased	2.3758	2.3985	0.0227
29	30	Unbiased	2.3526	2.3647	0.0121
30	20	Biased	2.3708	2.3719	0.0011
31	30	Unbiased	2.3773	2.3799	0.0026
33	30	Biased	2.3916	2.3985	0.0069
34	50	Unbiased	2.3187	2.3375	0.0188
35	20	Unbiased	2.3163	2.3171	0.0008
41	30	Biased	2.3707	2.3068	-0.0639

Test Statistics (Ω)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.3434	2.3784	2.4084	0.027339	2.3418	2.3869	2.4198	0.0337	-0.0016	0.00845	0.0152	0.007197
20	2.3163	2.3634	2.4049	0.030058	2.3171	2.3723	2.4084	0.027971	0.0008	0.0089	0.0228	0.007671
30	2.3113	2.3616	2.3967	0.03008	2.3068	2.3663	2.3985	0.031503	-0.0639	0.00477	0.0282	0.026171
50	2.3187	2.3566	2.3961	0.027174	2.3375	2.378	2.4192	0.028287	-0.001	0.02134	0.0405	0.012168

Device Test: 24.1 LEVEL|LOW_LEVEL/OUTL/4.5/4.5/0/0/4.5/500kHz//@OUT_VOL





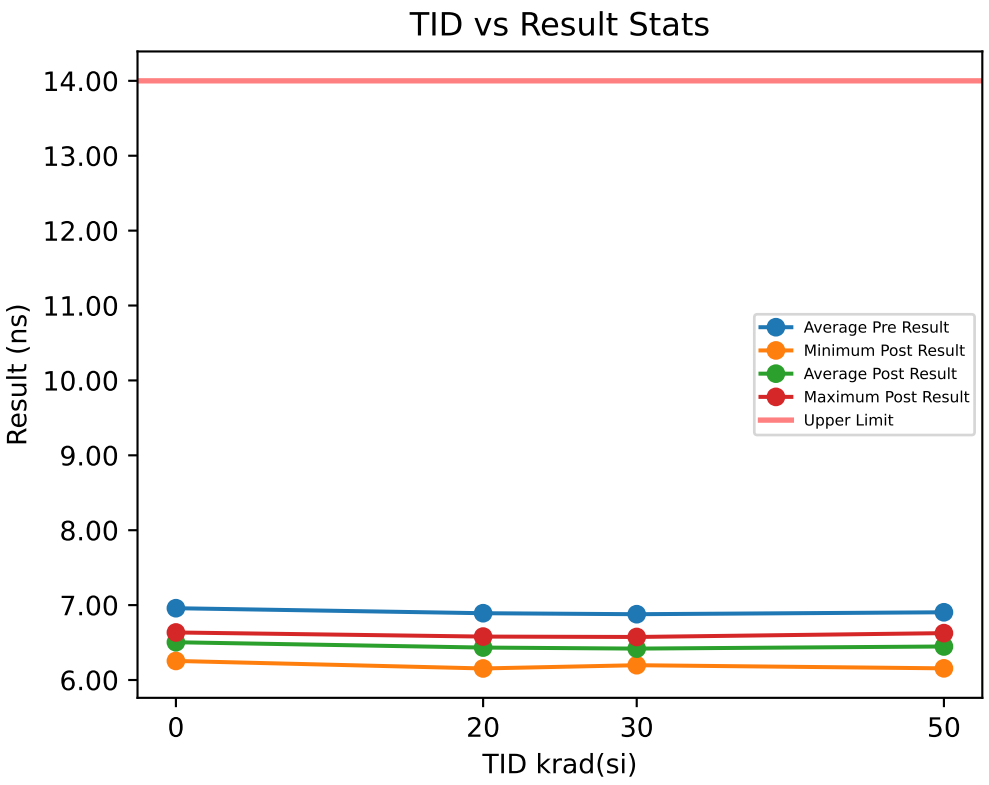
Test Results (Upper Limit = 0.15 (V))

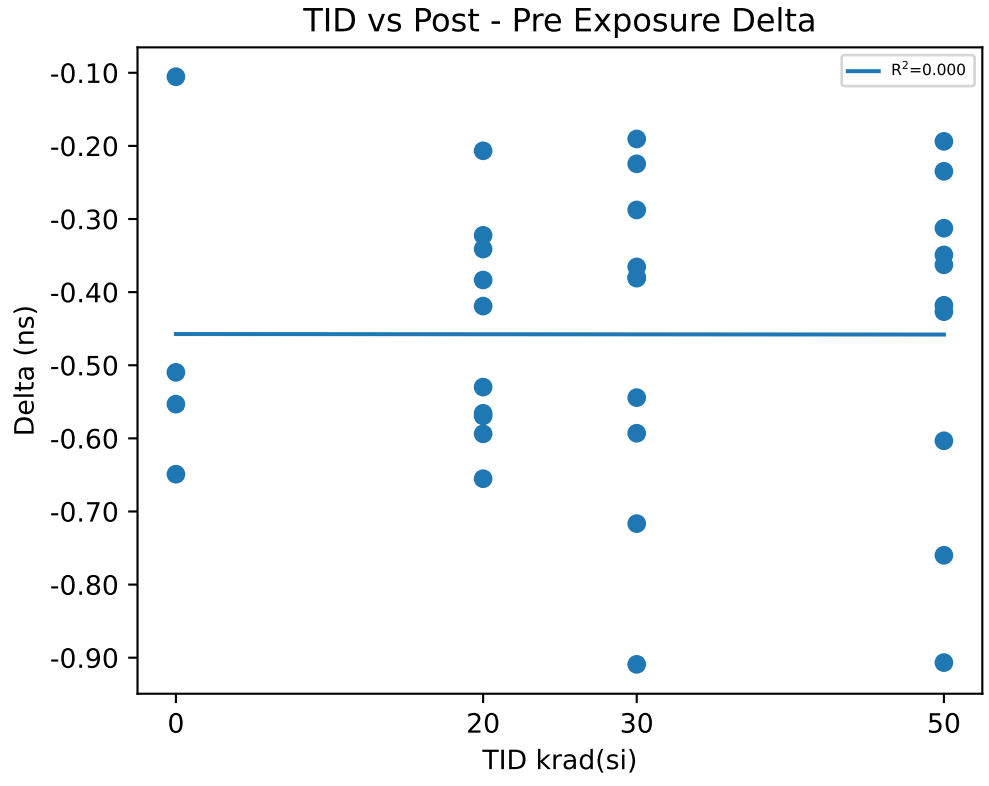
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	0.0832	0.0803	-0.0029
2	20	Unbiased	0.0833	0.0826	-0.0007
3	50	Biased	0.0833	0.0806	-0.0027
4	30	Unbiased	0.0832	0.0822	-0.001
5	50	Unbiased	0.0836	0.0826	-0.001
6	30	Biased	0.084	0.0816	-0.0024
7	50	Biased	0.084	0.0812	-0.0028
8	30	Unbiased	0.0831	0.0824	-0.0007
9	20	Unbiased	0.0837	0.0829	-0.0008
10	50	Biased	0.0842	0.0812	-0.003
11	30	Biased	0.0831	0.0803	-0.0028
12	0	Correlation	0.0841	0.0841	0
13	0	Correlation	0.0845	0.0844	-0.0001
14	50	Unbiased	0.0839	0.0826	-0.0013
15	20	Biased	0.0838	0.0814	-0.0024
16	20	Unbiased	0.0844	0.0834	-0.001
17	20	Biased	0.0845	0.0823	-0.0022
18	20	Unbiased	0.0846	0.0835	-0.0011
19	20	Biased	0.0836	0.0811	-0.0025
20	50	Unbiased	0.0844	0.0831	-0.0013
21	0	Correlation	0.0834	0.0832	-0.0002
22	50	Unbiased	0.0839	0.0822	-0.0017
23	0	Correlation	0.0846	0.0843	-0.0003
24	20	Biased	0.0845	0.0821	-0.0024
26	50	Biased	0.0841	0.081	-0.0031
27	30	Unbiased	0.0841	0.083	-0.0011
28	30	Biased	0.0842	0.081	-0.0032
29	30	Unbiased	0.083	0.082	-0.001
30	20	Biased	0.0843	0.0815	-0.0028
31	30	Unbiased	0.0839	0.0835	-0.0004
33	30	Biased	0.0848	0.0816	-0.0032
34	50	Unbiased	0.0834	0.082	-0.0014
35	20	Unbiased	0.0833	0.0822	-0.0011
41	30	Biased	0.0832	0.0817	-0.0015

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.0834	0.08415	0.0846	0.00054467	0.0832	0.084	0.0844	0.00054772	-0.0003	-0.00015	0	0.0001291
20	0.0833	0.084	0.0846	0.00051424	0.0811	0.0823	0.0835	0.00081921	-0.0028	-0.0017	-0.0007	0.00082327
30	0.083	0.08366	0.0848	0.0006186	0.0803	0.08193	0.0835	0.00092502	-0.0032	-0.00173	-0.0004	0.0010678
50	0.0832	0.0838	0.0844	0.00040552	0.0803	0.08168	0.0831	0.00094728	-0.0031	-0.00212	-0.001	0.00084564

Device Test: 24.10 TIMING|OUT_FALL/OUTH/4.5/4.5/0/1000/4.5/500kHz//@OUT_FALL_4P5V





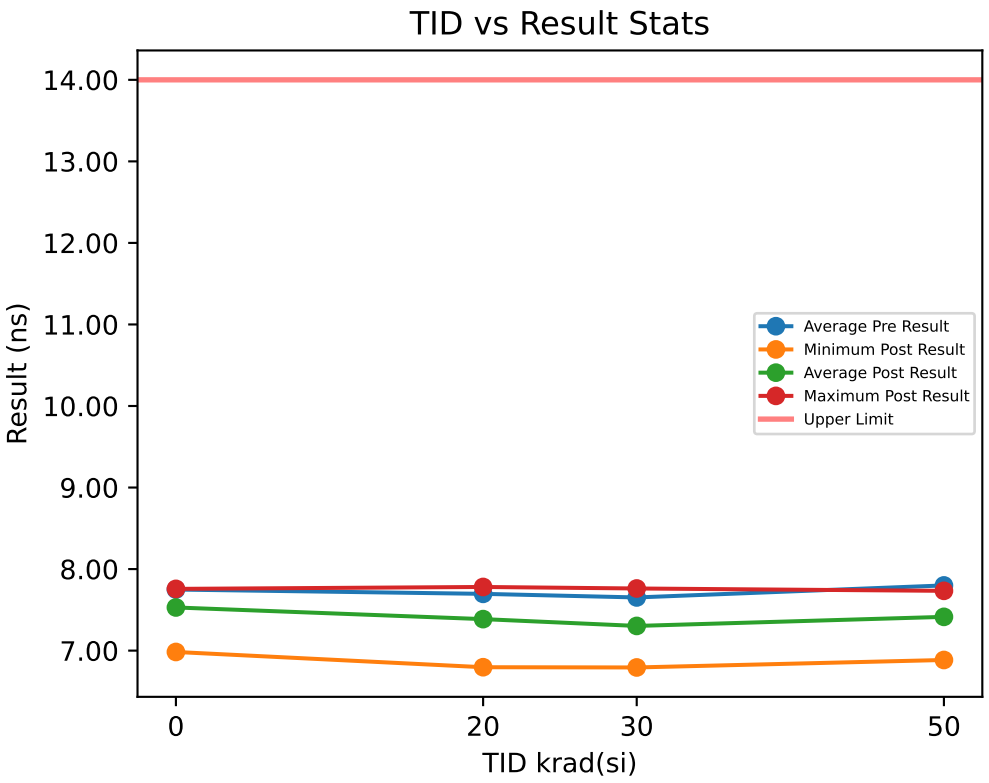
Test Results (Upper Limit = 14.0 (ns))

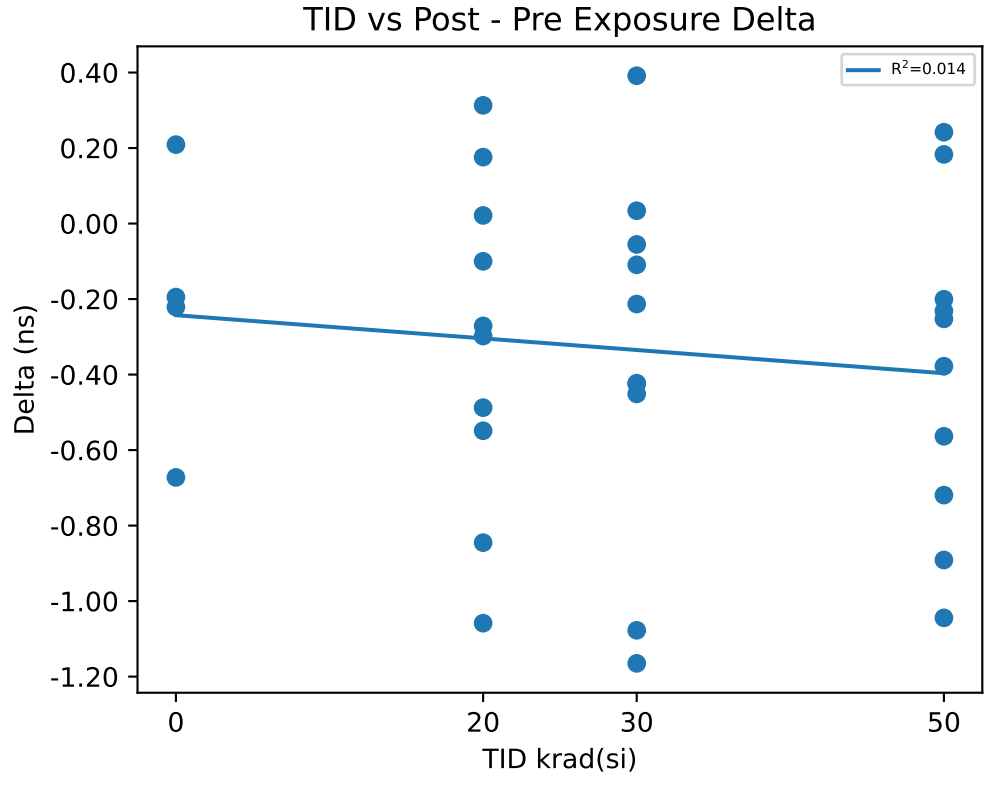
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	7.0464	6.4431	-0.6033
2	20	Unbiased	6.9006	6.4815	-0.4191
3	50	Biased	6.6771	6.4424	-0.2347
4	30	Unbiased	6.8622	6.5746	-0.2876
5	50	Unbiased	7.0867	6.18	-0.9067
6	30	Biased	6.9256	6.209	-0.7166
7	50	Biased	6.7193	6.5255	-0.1938
8	30	Unbiased	6.8894	6.5239	-0.3655
9	20	Unbiased	7.0437	6.5138	-0.5299
10	50	Biased	6.9156	6.1557	-0.7599
11	30	Biased	6.7419	6.1976	-0.5443
12	0	Correlation	6.9036	6.2546	-0.649
13	0	Correlation	7.1179	6.5647	-0.5532
14	50	Unbiased	6.9384	6.6258	-0.3126
15	20	Biased	6.7759	6.1821	-0.5938
16	20	Unbiased	6.8747	6.5524	-0.3223
17	20	Biased	7.0959	6.5302	-0.5657
18	20	Unbiased	6.9308	6.5474	-0.3834
19	20	Biased	6.6932	6.4865	-0.2067
20	50	Unbiased	6.9105	6.5614	-0.3491
21	0	Correlation	7.0727	6.563	-0.5097
22	50	Unbiased	6.9239	6.5613	-0.3626
23	0	Correlation	6.7401	6.6347	-0.1054
24	20	Biased	6.9209	6.5798	-0.3411
26	50	Biased	6.9466	6.5199	-0.4267
27	30	Unbiased	6.758	6.5675	-0.1905
28	30	Biased	6.8944	6.5135	-0.3809
29	30	Unbiased	7.0648	6.4718	-0.593
30	20	Biased	6.9588	6.3036	-0.6552
31	30	Unbiased	6.7417	6.5172	-0.2245
33	30	Biased	7.1219	6.2128	-0.9091
34	50	Unbiased	6.8782	6.4602	-0.418
35	20	Unbiased	6.7235	6.1542	-0.5693
41	30	Biased	6.7853	6.4056	-0.3797

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.7401	6.9586	7.1179	0.1724	6.2546	6.5042	6.6347	0.16975	-0.649	-0.45433	-0.1054	0.23978
20	6.6932	6.8918	7.0959	0.13045	6.1542	6.4332	6.5798	0.15899	-0.6552	-0.45865	-0.2067	0.14483
30	6.7417	6.8785	7.1219	0.13224	6.1976	6.4193	6.5746	0.15436	-0.9091	-0.45917	-0.1905	0.22895
50	6.6771	6.9043	7.0867	0.12627	6.1557	6.4475	6.6258	0.15845	-0.9067	-0.45674	-0.1938	0.23044

Device Test: 24.11 TIMING|OUT_RISE/OUTH/5/5/0/1000/5/500kHz//@OUT_RISE_5V





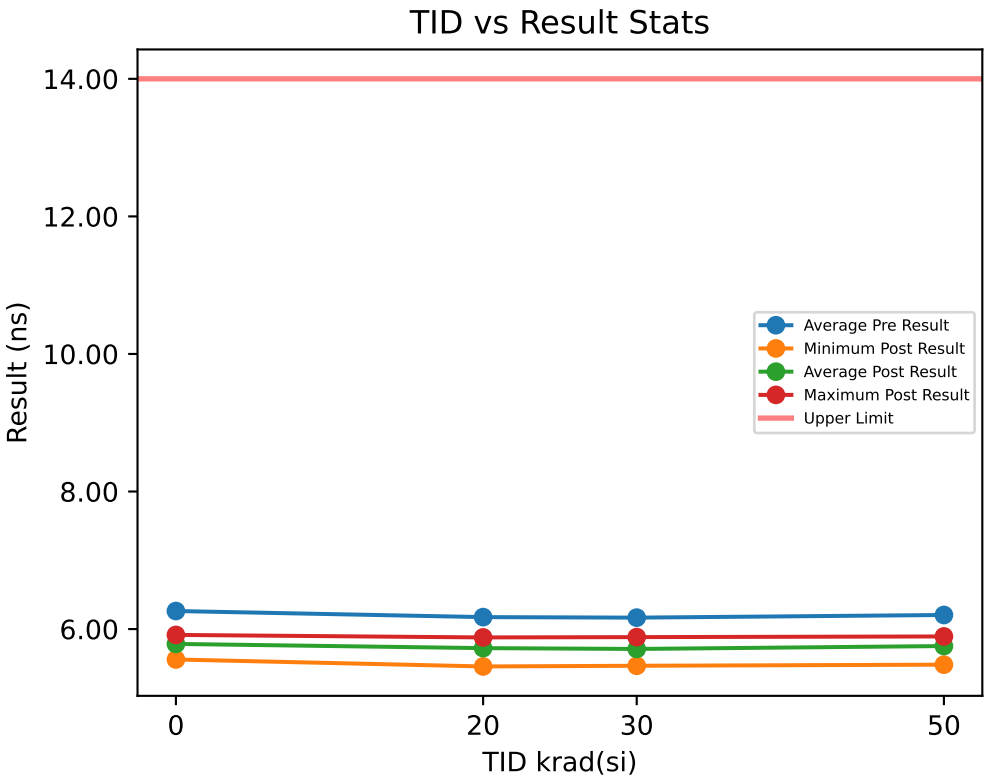
Test Results (Upper Limit = 14.0 (ns))

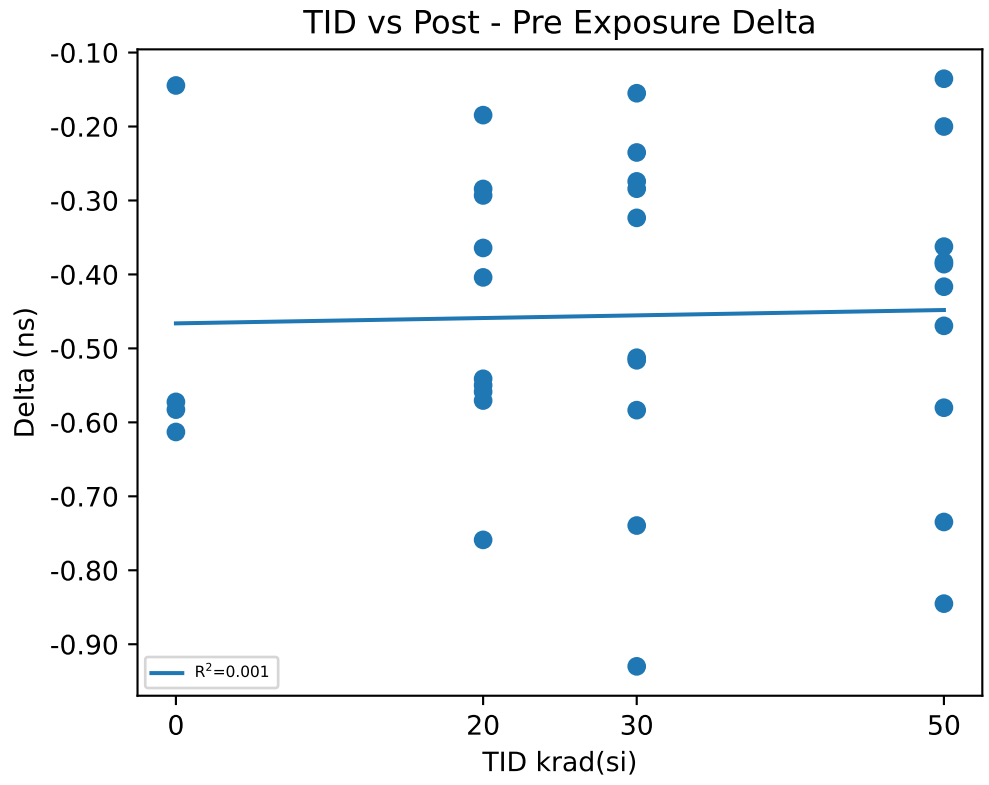
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	7.8386	7.6382	-0.2004
2	20	Unbiased	7.8123	7.7123	-0.1
3	50	Biased	7.3676	7.5507	0.1831
4	30	Unbiased	7.5327	7.3195	-0.2132
5	50	Unbiased	7.9984	7.1073	-0.8911
6	30	Biased	8.0316	6.9542	-1.0774
7	50	Biased	7.4086	7.6505	0.2419
8	30	Unbiased	7.631	7.5757	-0.0553
9	20	Unbiased	7.9114	7.0662	-0.8452
10	50	Biased	7.9295	6.8851	-1.0444
11	30	Biased	7.3766	6.9519	-0.4247
12	0	Correlation	7.6558	6.9834	-0.6724
13	0	Correlation	7.9783	7.7572	-0.2211
14	50	Unbiased	7.9477	7.2284	-0.7193
15	20	Biased	7.4096	6.922	-0.4876
16	20	Unbiased	7.6047	7.7806	0.1759
17	20	Biased	7.9582	7.6602	-0.298
18	20	Unbiased	8.0029	7.7318	-0.2711
19	20	Biased	7.3005	7.6136	0.3131
20	50	Unbiased	7.7338	7.3559	-0.3779
21	0	Correlation	7.8786	7.6838	-0.1948
22	50	Unbiased	7.9584	7.3949	-0.5635
23	0	Correlation	7.4833	7.6924	0.2091
24	20	Biased	7.6497	7.6712	0.0215
26	50	Biased	7.9646	7.7332	-0.2314
27	30	Unbiased	7.4378	7.3285	-0.1093
28	30	Biased	7.6872	7.7212	0.034
29	30	Unbiased	7.8837	7.4325	-0.4512
30	20	Biased	7.9674	6.9089	-1.0585
31	30	Unbiased	7.3705	7.762	0.3915
33	30	Biased	7.9584	6.7935	-1.1649
34	50	Unbiased	7.8479	7.5954	-0.2525
35	20	Unbiased	7.3453	6.7964	-0.5489
41	30	Biased	7.6116	7.1888	-0.4228

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.4833	7.749	7.9783	0.2226	6.9834	7.5292	7.7572	0.36534	-0.6724	-0.2198	0.2091	0.36029
20	7.3005	7.6962	8.0029	0.27253	6.7964	7.3863	7.7806	0.40592	-1.0585	-0.30988	0.3131	0.43657
30	7.3705	7.6521	8.0316	0.23809	6.7935	7.3028	7.762	0.33253	-1.1649	-0.34933	0.3915	0.48017
50	7.3676	7.7995	7.9984	0.23057	6.8851	7.414	7.7332	0.27318	-1.0444	-0.38555	0.2419	0.42499

Device Test: 24.12 TIMING|OUT_FALL/OUTH/5/5/0/1000/5/500kHz//@OUT_FALL_5V





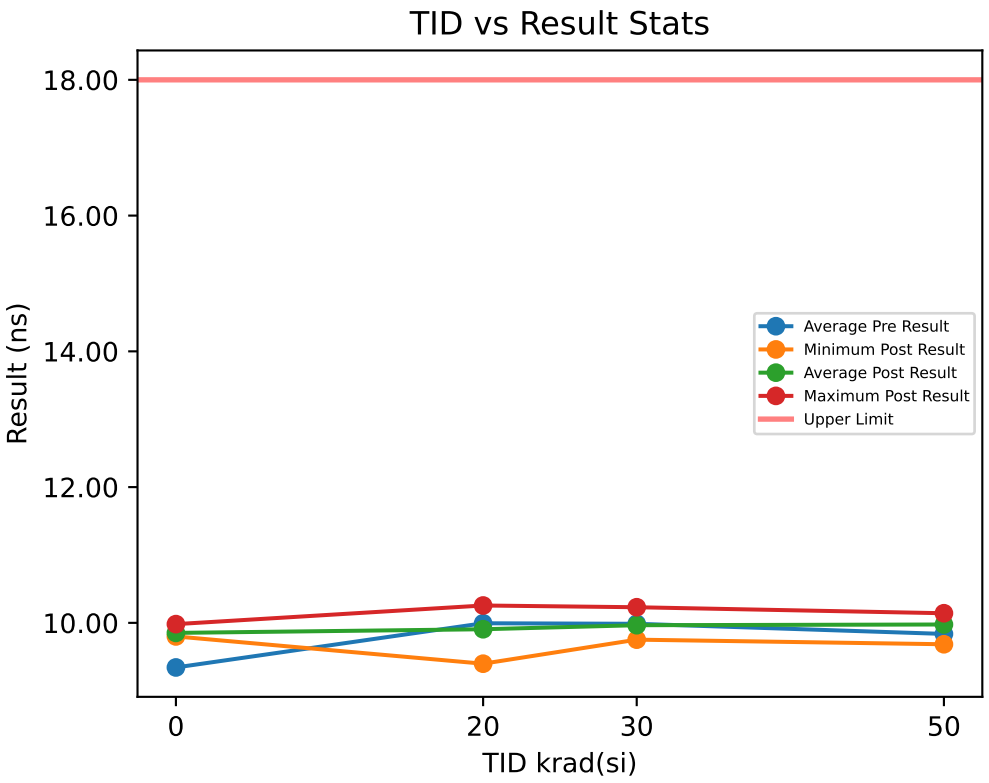
Test Results (Upper Limit = 14.0 (ns))

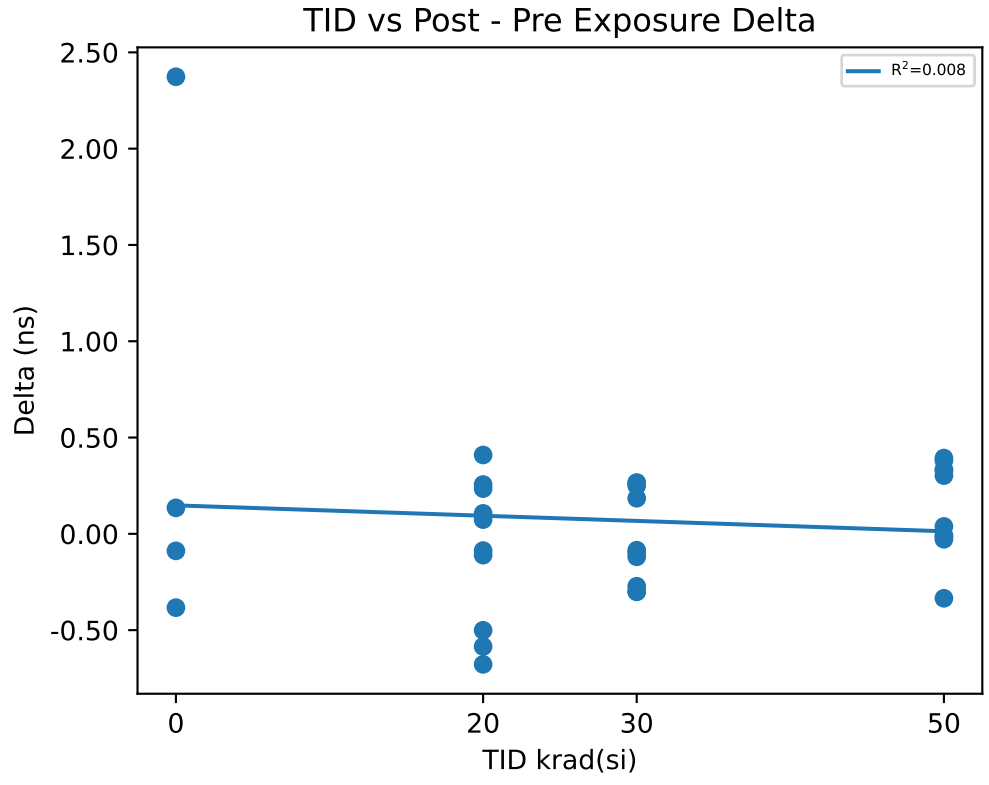
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	6.3522	5.772	-0.5802
2	20	Unbiased	6.2025	5.7985	-0.404
3	50	Biased	5.9325	5.7971	-0.1354
4	30	Unbiased	6.0924	5.8182	-0.2742
5	50	Unbiased	6.3753	5.5302	-0.8451
6	30	Biased	6.2364	5.4969	-0.7395
7	50	Biased	6.0492	5.8492	-0.2
8	30	Unbiased	6.1397	5.8162	-0.3235
9	20	Unbiased	6.3502	5.7797	-0.5705
10	50	Biased	6.2172	5.4825	-0.7347
11	30	Biased	5.9826	5.4665	-0.5161
12	0	Correlation	6.1709	5.5579	-0.613
13	0	Correlation	6.4365	5.8537	-0.5828
14	50	Unbiased	6.2477	5.7782	-0.4695
15	20	Biased	6.0321	5.4735	-0.5586
16	20	Unbiased	6.1399	5.8555	-0.2844
17	20	Biased	6.3934	5.8435	-0.5499
18	20	Unbiased	6.2428	5.8786	-0.3642
19	20	Biased	5.9498	5.7652	-0.1846
20	50	Unbiased	6.1818	5.7988	-0.383
21	0	Correlation	6.3826	5.8103	-0.5723
22	50	Unbiased	6.2452	5.8286	-0.4166
23	0	Correlation	6.0595	5.915	-0.1445
24	20	Biased	6.1595	5.8663	-0.2932
26	50	Biased	6.2553	5.8929	-0.3624
27	30	Unbiased	6.064	5.8289	-0.2351
28	30	Biased	6.1529	5.8688	-0.2841
29	30	Unbiased	6.3739	5.7904	-0.5835
30	20	Biased	6.2713	5.5124	-0.7589
31	30	Unbiased	6.0381	5.8831	-0.155
33	30	Biased	6.4018	5.4719	-0.9299
34	50	Unbiased	6.1898	5.8037	-0.3861
35	20	Unbiased	5.9976	5.4565	-0.5411
41	30	Biased	6.1806	5.668	-0.5126

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.0595	6.2624	6.4365	0.17729	5.5579	5.7842	5.915	0.15688	-0.613	-0.47815	-0.1445	0.2231
20	5.9498	6.1739	6.3934	0.14798	5.4565	5.723	5.8786	0.17164	-0.7589	-0.45094	-0.1846	0.17382
30	5.9826	6.1662	6.4018	0.13771	5.4665	5.7109	5.8831	0.17059	-0.9299	-0.45535	-0.155	0.24666
50	5.9325	6.2046	6.3753	0.13169	5.4825	5.7533	5.8929	0.13538	-0.8451	-0.4513	-0.1354	0.21942

Device Test: 24.13 TIMING|OUT_RISE/OUTH/12/12/0/1000/5/500kHz//@OUT_RISE_12V





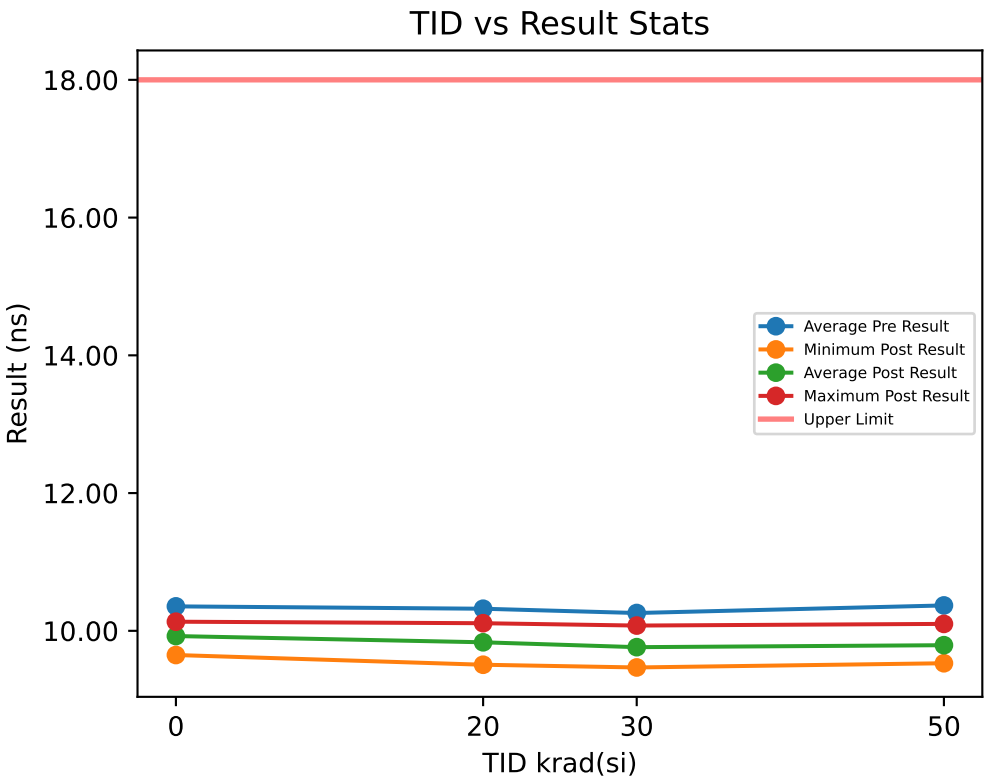
Test Results (Upper Limit = 18.0 (ns))

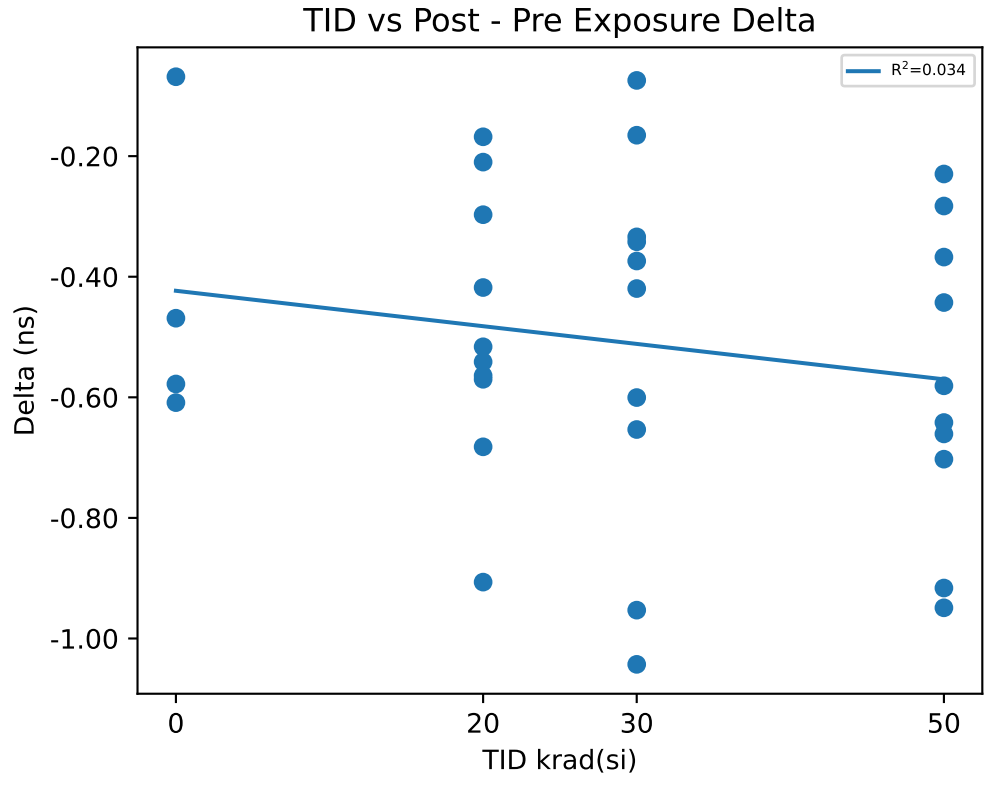
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	9.8147	10.117	0.3024
2	20	Unbiased	10.193	9.5149	-0.6777
3	50	Biased	9.713	9.6848	-0.0282
4	30	Unbiased	10.117	9.8153	-0.3012
5	50	Unbiased	10.12	10.112	-0.0079
6	30	Biased	9.7698	10.02	0.2501
7	50	Biased	9.9489	9.9325	-0.0164
8	30	Unbiased	10.17	9.8977	-0.2721
9	20	Unbiased	10.011	9.9245	-0.0869
10	50	Biased	9.6392	10.019	0.3801
11	30	Biased	9.8127	9.9975	0.1848
12	0	Correlation	7.4482	9.8216	2.3734
13	0	Correlation	10.189	9.8056	-0.3833
14	50	Unbiased	9.7082	10.042	0.3336
15	20	Biased	10.145	10.251	0.1063
16	20	Unbiased	9.7616	10.018	0.2561
17	20	Biased	10.258	10.147	-0.1106
18	20	Unbiased	9.8464	10.256	0.4094
19	20	Biased	10.161	9.5756	-0.585
20	50	Unbiased	10.085	9.7503	-0.3346
21	0	Correlation	9.8884	9.8	-0.0884
22	50	Unbiased	9.6011	9.9305	0.3294
23	0	Correlation	9.8463	9.9812	0.1349
24	20	Biased	9.9979	10.072	0.0739
26	50	Biased	9.7483	10.142	0.3934
27	30	Unbiased	9.9681	10.23	0.262
28	30	Biased	9.9215	9.8022	-0.1193
29	30	Unbiased	10.051	9.7525	-0.2986
30	20	Biased	9.6674	9.9022	0.2348
31	30	Unbiased	9.8794	10.146	0.2665
33	30	Biased	10.193	10.095	-0.0981
34	50	Unbiased	9.9911	10.03	0.0385
35	20	Unbiased	9.8991	9.3983	-0.5008
41	30	Biased	9.9824	9.8973	-0.0851

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.4482	9.343	10.189	1.2723	9.8	9.8521	9.9812	0.086552	-0.3833	0.50915	2.3734	1.2608
20	9.6674	9.9939	10.258	0.19753	9.3983	9.9059	10.256	0.30906	-0.6777	-0.08805	0.4094	0.38001
30	9.7698	9.9864	10.193	0.14545	9.7525	9.9653	10.23	0.15883	-0.3012	-0.0211	0.2665	0.23966
50	9.6011	9.8369	10.12	0.18645	9.6848	9.976	10.142	0.15443	-0.3346	0.13903	0.3934	0.24307

Device Test: 24.14 TIMING|OUT_FALL/OUTH/12/12/0/1000/5/500kHz//@OUT_FALL_12V





Test Results (Upper Limit = 18.0 (ns))

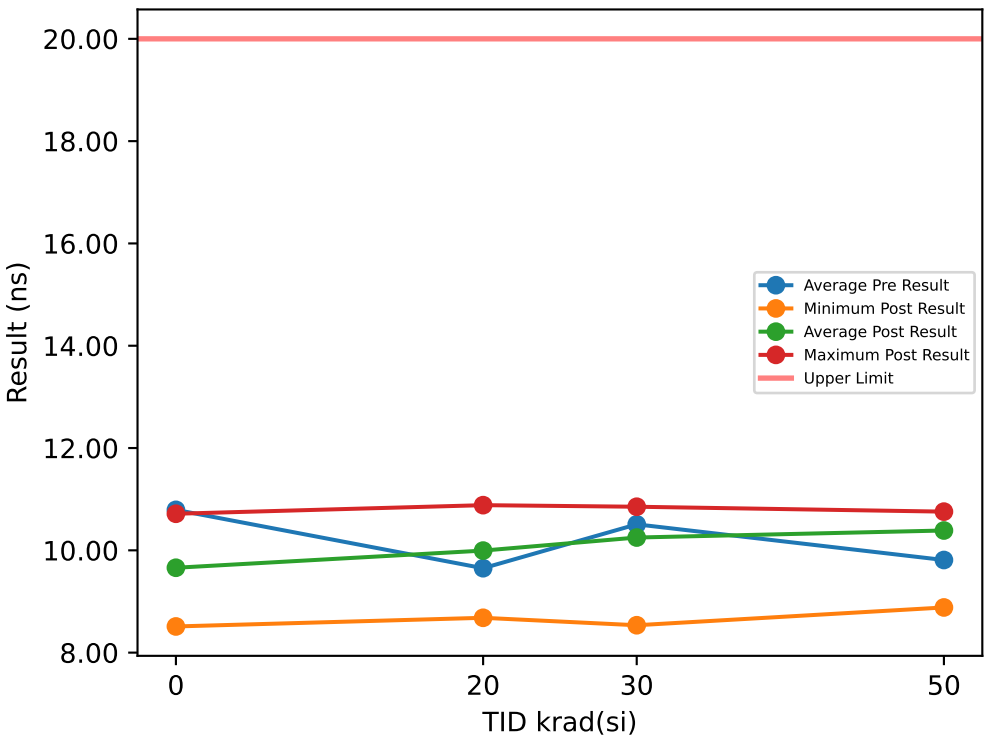
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	10.454	9.8119	-0.6418
2	20	Unbiased	10.424	9.8598	-0.5641
3	50	Biased	10.014	9.7847	-0.2296
4	30	Unbiased	10.115	9.7407	-0.3739
5	50	Unbiased	10.487	9.5703	-0.9163
6	30	Biased	10.501	9.5475	-0.953
7	50	Biased	10.186	9.9036	-0.2827
8	30	Unbiased	10.175	10.009	-0.1653
9	20	Unbiased	10.45	9.7683	-0.6821
10	50	Biased	10.478	9.5293	-0.9491
11	30	Biased	10.11	9.5096	-0.6004
12	0	Correlation	10.227	9.6489	-0.5779
13	0	Correlation	10.55	9.9411	-0.6088
14	50	Unbiased	10.475	9.7726	-0.7026
15	20	Biased	10.116	9.5459	-0.5701
16	20	Unbiased	10.251	10.083	-0.1679
17	20	Biased	10.533	10.017	-0.5162
18	20	Unbiased	10.528	10.111	-0.4179
19	20	Biased	10.076	9.7787	-0.2971
20	50	Unbiased	10.216	9.8487	-0.3674
21	0	Correlation	10.443	9.9742	-0.4688
22	50	Unbiased	10.46	9.7992	-0.6607
23	0	Correlation	10.201	10.133	-0.0683
24	20	Biased	10.238	10.028	-0.2099
26	50	Biased	10.543	10.101	-0.4428
27	30	Unbiased	10.196	9.8541	-0.342
28	30	Biased	10.205	9.8711	-0.3339
29	30	Unbiased	10.451	9.7972	-0.6534
30	20	Biased	10.543	9.6361	-0.9065
31	30	Unbiased	10.151	10.077	-0.0744
33	30	Biased	10.511	9.4682	-1.0429
34	50	Unbiased	10.373	9.7924	-0.5809
35	20	Unbiased	10.049	9.5077	-0.5412
41	30	Biased	10.173	9.7537	-0.4196

Test Statistics (ns)

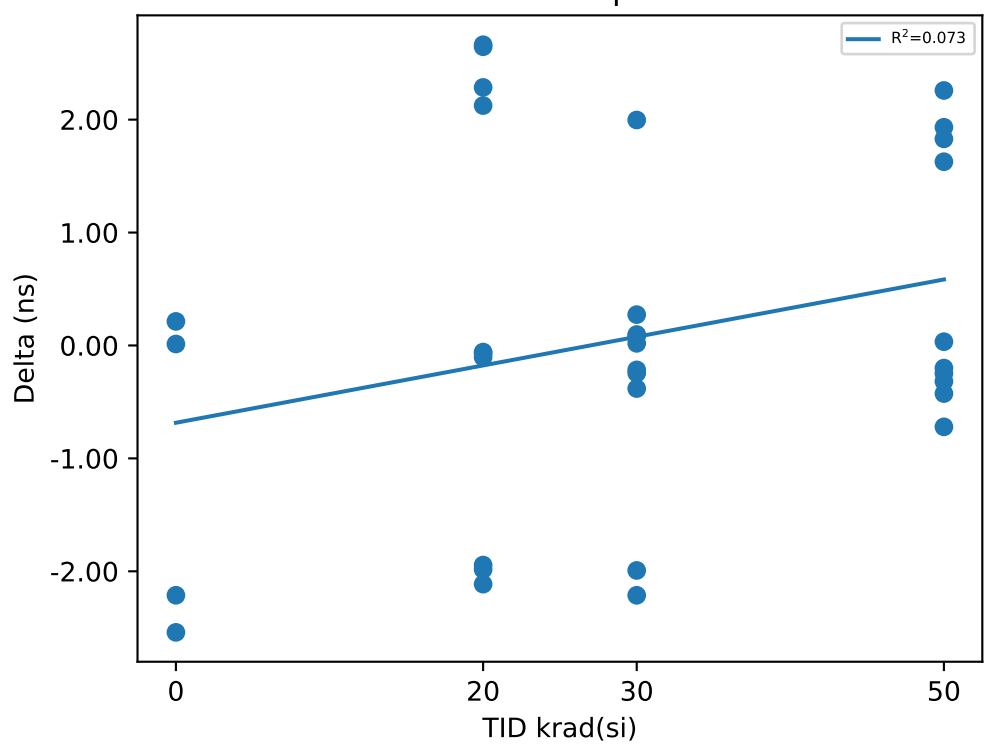
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	10.201	10.355	10.55	0.16926	9.6489	9.9242	10.133	0.20163	-0.6088	-0.43095	-0.0683	0.24911
20	10.049	10.321	10.543	0.19789	9.5077	9.8336	10.111	0.22273	-0.9065	-0.4873	-0.1679	0.22364
30	10.11	10.259	10.511	0.16146	9.4682	9.7628	10.077	0.20504	-1.0429	-0.49588	-0.0744	0.31649
50	10.014	10.369	10.543	0.17177	9.5293	9.7913	10.101	0.15986	-0.9491	-0.57739	-0.2296	0.24717

Device Test: 24.15 TIMING|OUT_RISE/OUTH/14/14/0/1000/5/500kHz//@OUT_RISE_14V

TID vs Result Stats



TID vs Post - Pre Exposure Delta



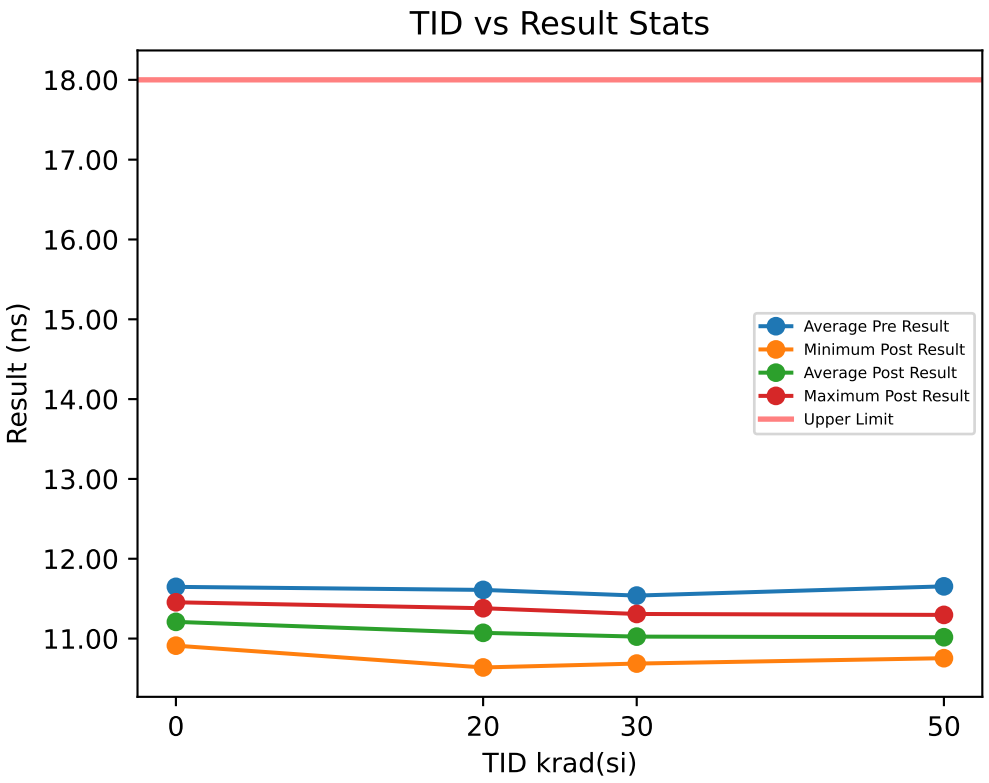
Test Results (Upper Limit = 20.0 (ns))

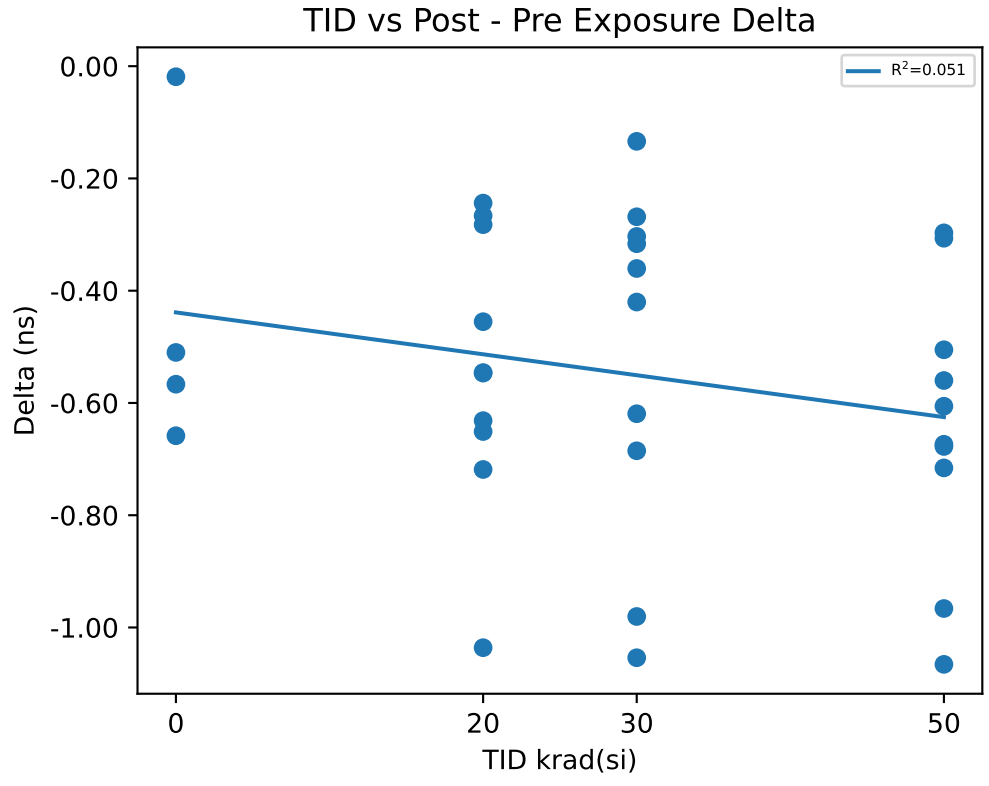
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	10.948	10.522	-0.4258
2	20	Unbiased	8.5903	10.876	2.2852
3	50	Biased	10.947	10.747	-0.2
4	30	Unbiased	10.694	10.713	0.0187
5	50	Unbiased	11.075	10.757	-0.3184
6	30	Biased	8.8555	10.852	1.9968
7	50	Biased	10.652	10.404	-0.2478
8	30	Unbiased	10.748	8.5355	-2.2125
9	20	Unbiased	10.706	10.648	-0.0584
10	50	Biased	8.7752	10.708	1.9324
11	30	Biased	10.749	10.846	0.0971
12	0	Correlation	10.577	10.59	0.0129
13	0	Correlation	10.502	10.715	0.2131
14	50	Unbiased	8.8403	10.468	1.6273
15	20	Biased	10.743	10.639	-0.1045
16	20	Unbiased	10.795	8.681	-2.1138
17	20	Biased	10.93	8.9851	-1.9446
18	20	Unbiased	8.9776	8.9089	-0.0687
19	20	Biased	8.0654	10.729	2.6633
20	50	Unbiased	10.981	10.26	-0.7208
21	0	Correlation	11.052	8.5117	-2.5407
22	50	Unbiased	8.6775	10.507	1.8295
23	0	Correlation	11.033	8.8212	-2.2121
24	20	Biased	10.84	8.8562	-1.9839
26	50	Biased	8.8497	8.8831	0.0334
27	30	Unbiased	10.669	10.424	-0.2444
28	30	Biased	10.709	10.493	-0.2161
29	30	Unbiased	10.491	10.573	0.0829
30	20	Biased	8.7585	10.883	2.1246
31	30	Unbiased	10.839	8.8465	-1.9924
33	30	Biased	10.432	10.706	0.2731
34	50	Unbiased	8.3632	10.621	2.2582
35	20	Unbiased	8.0986	10.744	2.6455
41	30	Biased	10.894	10.512	-0.3815

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	10.502	10.791	11.052	0.29234	8.5117	9.6595	10.715	1.1547	-2.5407	-1.1317	0.2131	1.4458
20	8.0654	9.6504	10.93	1.2456	8.681	9.9949	10.883	0.98471	-2.1138	0.34447	2.6633	1.9677
30	8.8555	10.508	10.894	0.59739	8.5355	10.25	10.852	0.83748	-2.2125	-0.25783	1.9968	1.1799
50	8.3632	9.8109	11.075	1.1821	8.8831	10.388	10.757	0.55188	-0.7208	0.5768	2.2582	1.1741

Device Test: 24.16 TIMING|OUT_FALL/OUTH/14/14/0/1000/5/500kHz//@OUT_FALL_14V





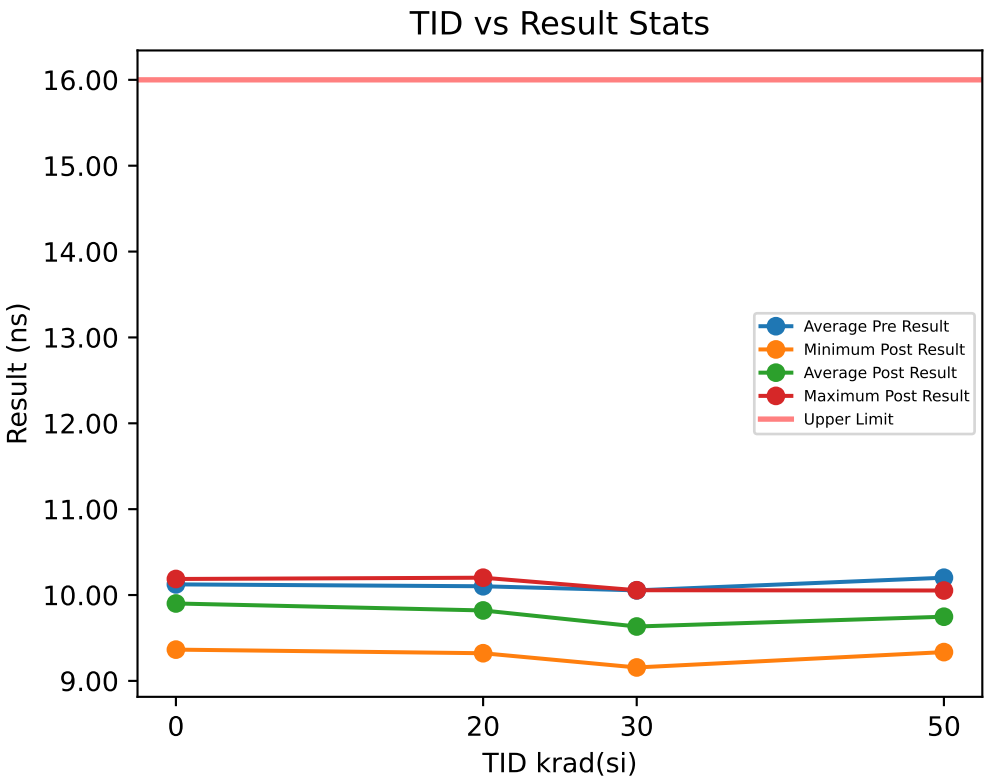
Test Results (Upper Limit = 18.0 (ns))

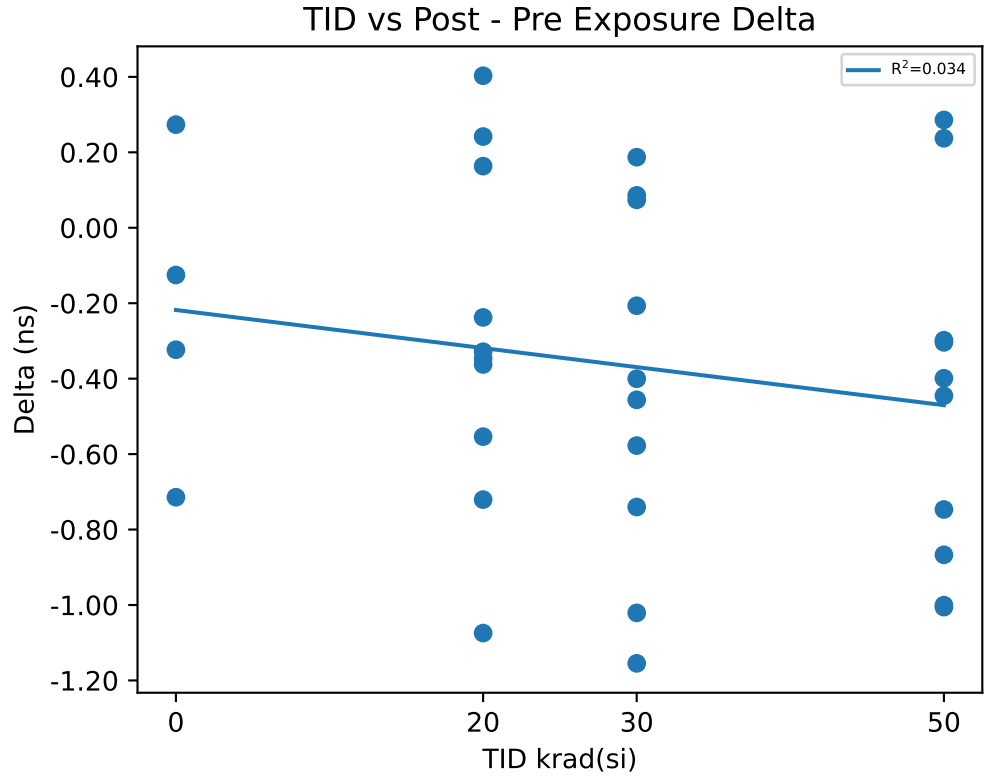
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	11.764	11.048	-0.7157
2	20	Unbiased	11.663	11.117	-0.5468
3	50	Biased	11.269	10.962	-0.3065
4	30	Unbiased	11.411	11.05	-0.3604
5	50	Unbiased	11.78	10.814	-0.9662
6	30	Biased	11.768	10.788	-0.9804
7	50	Biased	11.447	11.15	-0.2969
8	30	Unbiased	11.475	11.206	-0.2683
9	20	Unbiased	11.759	11.041	-0.7185
10	50	Biased	11.82	10.754	-1.0657
11	30	Biased	11.306	10.687	-0.6192
12	0	Correlation	11.57	10.911	-0.6584
13	0	Correlation	11.844	11.277	-0.5666
14	50	Unbiased	11.739	11.065	-0.6736
15	20	Biased	11.375	10.743	-0.6315
16	20	Unbiased	11.622	11.356	-0.2664
17	20	Biased	11.851	11.306	-0.5459
18	20	Unbiased	11.835	11.38	-0.4552
19	20	Biased	11.296	11.052	-0.2439
20	50	Unbiased	11.561	11.056	-0.5052
21	0	Correlation	11.704	11.194	-0.51
22	50	Unbiased	11.697	11.019	-0.6775
23	0	Correlation	11.473	11.455	-0.0188
24	20	Biased	11.573	11.29	-0.2823
26	50	Biased	11.857	11.297	-0.56
27	30	Unbiased	11.435	11.132	-0.3033
28	30	Biased	11.533	11.112	-0.4202
29	30	Unbiased	11.729	11.043	-0.6852
30	20	Biased	11.833	10.797	-1.036
31	30	Unbiased	11.442	11.308	-0.1339
33	30	Biased	11.804	10.75	-1.0539
34	50	Unbiased	11.607	11.002	-0.6058
35	20	Unbiased	11.289	10.638	-0.6509
41	30	Biased	11.485	11.168	-0.3163

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	11.473	11.648	11.844	0.16149	10.911	11.209	11.455	0.22651	-0.6584	-0.43845	-0.0188	0.28637
20	11.289	11.61	11.851	0.22175	10.638	11.072	11.38	0.26933	-1.036	-0.53774	-0.2439	0.24375
30	11.306	11.539	11.804	0.16894	10.687	11.025	11.308	0.21078	-1.0539	-0.51411	-0.1339	0.31093
50	11.269	11.654	11.857	0.18476	10.754	11.017	11.297	0.15438	-1.0657	-0.63731	-0.2969	0.24732

Device Test: 24.17 TIMING|OUT_RISE/OUTH/4.5/12/0/1000/4.5/500kHz//@OUT_RISE_LDO





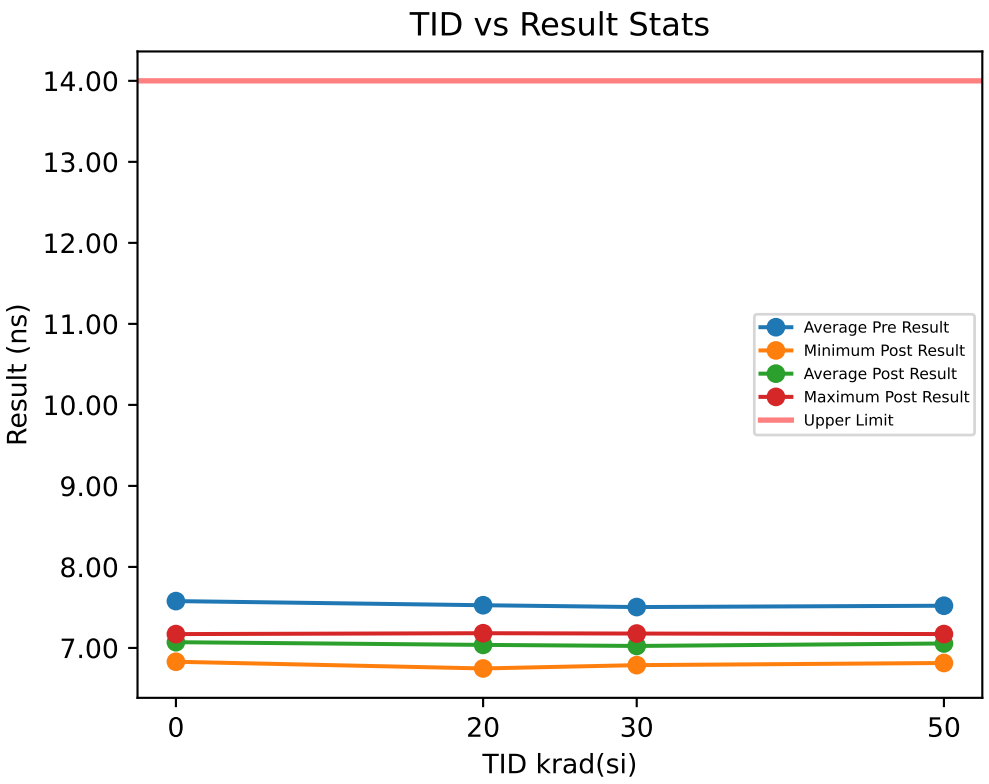
Test Results (Upper Limit = 16.0 (ns))

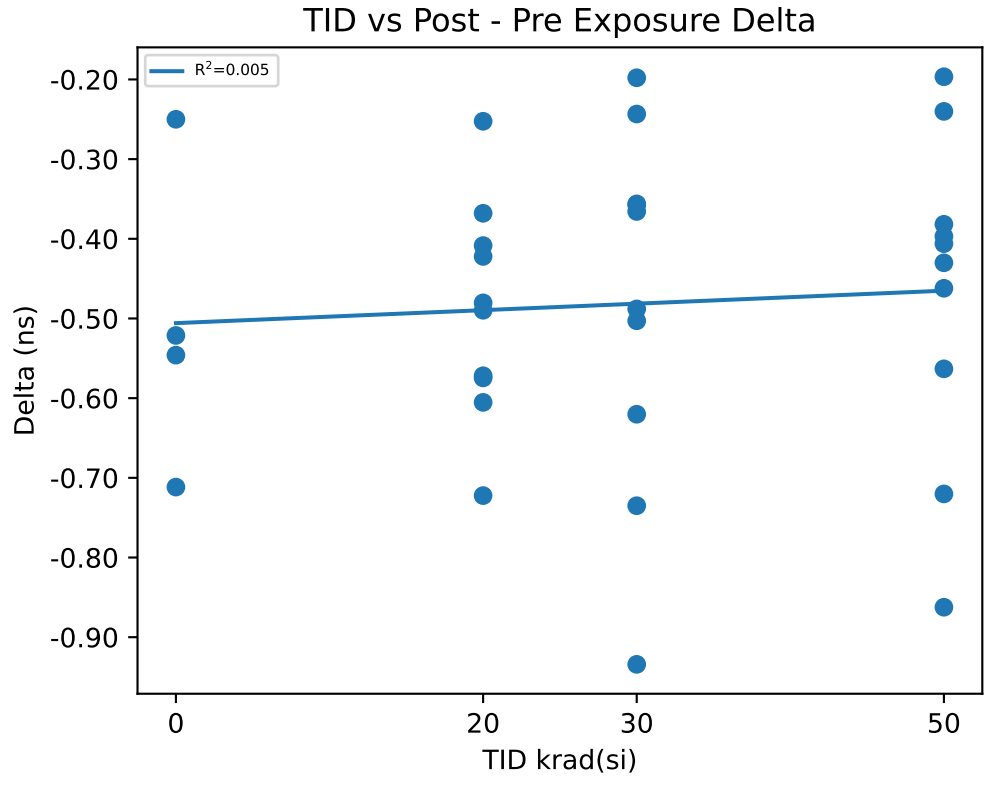
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	10.257	9.9584	-0.2981
2	20	Unbiased	10.32	9.973	-0.3469
3	50	Biased	9.7837	10.021	0.2372
4	30	Unbiased	9.9583	9.5022	-0.4561
5	50	Unbiased	10.409	9.4082	-1.0004
6	30	Biased	10.366	9.2113	-1.1547
7	50	Biased	9.767	10.053	0.2858
8	30	Unbiased	9.9818	10.056	0.074
9	20	Unbiased	10.29	9.5696	-0.7206
10	50	Biased	10.341	9.3353	-1.0056
11	30	Biased	9.7339	9.1565	-0.5774
12	0	Correlation	10.079	9.3642	-0.7143
13	0	Correlation	10.296	9.973	-0.3233
14	50	Unbiased	10.302	9.5551	-0.7468
15	20	Biased	9.8879	9.3342	-0.5537
16	20	Unbiased	9.9729	10.136	0.1634
17	20	Biased	10.39	10.028	-0.3624
18	20	Unbiased	10.353	10.116	-0.2377
19	20	Biased	9.715	10.118	0.403
20	50	Unbiased	10.016	9.7122	-0.3038
21	0	Correlation	10.312	10.187	-0.1252
22	50	Unbiased	10.382	9.5152	-0.867
23	0	Correlation	9.8093	10.083	0.2734
24	20	Biased	9.96	10.202	0.2418
26	50	Biased	10.406	9.9604	-0.4453
27	30	Unbiased	9.7847	9.578	-0.2067
28	30	Biased	9.9618	10.048	0.0859
29	30	Unbiased	10.295	9.8944	-0.4002
30	20	Biased	10.397	9.3222	-1.0744
31	30	Unbiased	9.838	10.025	0.1871
33	30	Biased	10.418	9.3971	-1.0209
34	50	Unbiased	10.354	9.9554	-0.3989
35	20	Unbiased	9.7352	9.4066	-0.3286
41	30	Biased	10.206	9.4662	-0.7402

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	9.8093	10.124	10.312	0.23535	9.3642	9.9017	10.187	0.36882	-0.7143	-0.22235	0.2734	0.41126
20	9.715	10.102	10.397	0.27543	9.3222	9.8205	10.202	0.36604	-1.0744	-0.28161	0.403	0.45349
30	9.7339	10.054	10.418	0.24843	9.1565	9.6334	10.056	0.34662	-1.1547	-0.42092	0.1871	0.46475
50	9.767	10.202	10.409	0.25186	9.3353	9.7474	10.053	0.27452	-1.0056	-0.45429	0.2858	0.46358

Device Test: 24.18 TIMING|OUT_FALL/OUTH/4.5/12/0/1000/4.5/500kHz//@OUT_FALL_LDO





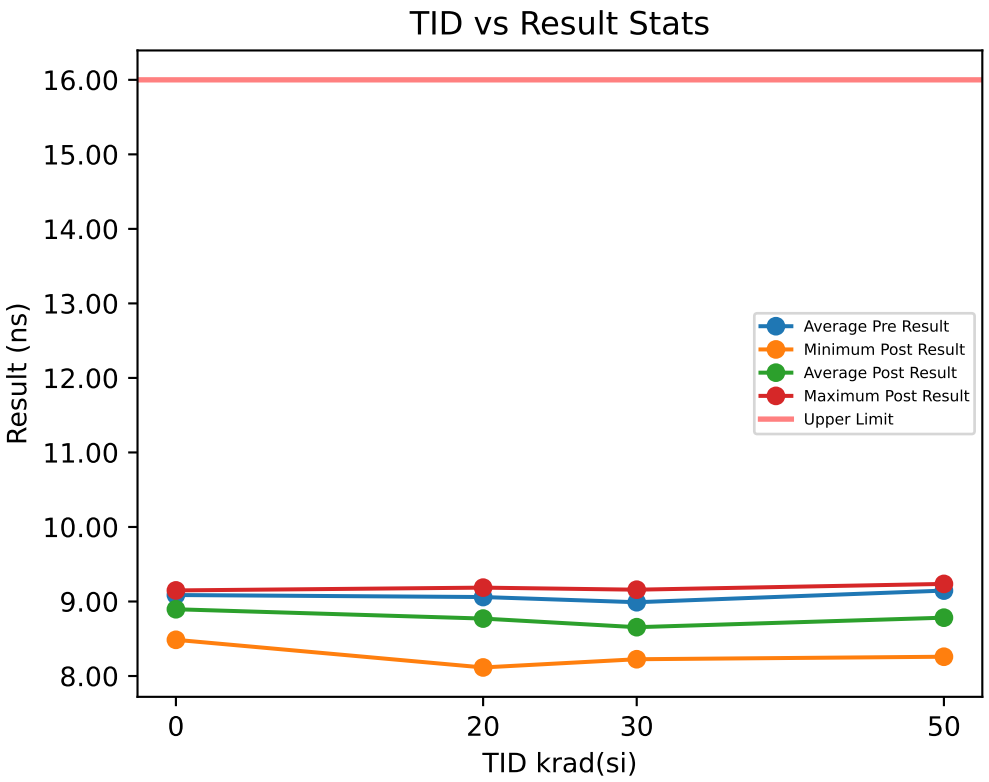
Test Results (Upper Limit = 14.0 (ns))

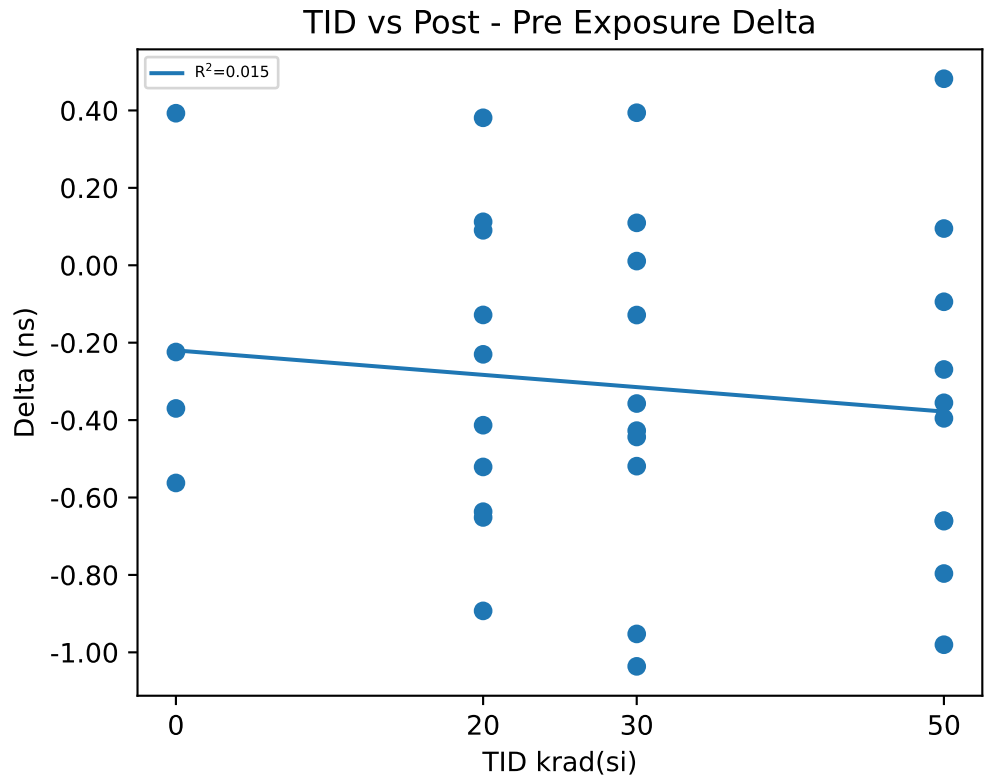
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	7.6681	7.1049	-0.5632
2	20	Unbiased	7.5058	7.0837	-0.4221
3	50	Biased	7.2926	7.0525	-0.2401
4	30	Unbiased	7.4775	7.1213	-0.3562
5	50	Unbiased	7.69	6.8276	-0.8624
6	30	Biased	7.5684	6.8334	-0.735
7	50	Biased	7.3643	7.1677	-0.1966
8	30	Unbiased	7.5056	7.1482	-0.3574
9	20	Unbiased	7.6714	7.1817	-0.4897
10	50	Biased	7.5343	6.8141	-0.7202
11	30	Biased	7.3118	6.8089	-0.5029
12	0	Correlation	7.5412	6.8296	-0.7116
13	0	Correlation	7.7169	7.1709	-0.546
14	50	Unbiased	7.5352	7.1051	-0.4301
15	20	Biased	7.4061	6.8342	-0.5719
16	20	Unbiased	7.5376	7.1696	-0.368
17	20	Biased	7.7084	7.1338	-0.5746
18	20	Unbiased	7.5489	7.1404	-0.4085
19	20	Biased	7.3606	7.1081	-0.2525
20	50	Unbiased	7.5186	7.1368	-0.3818
21	0	Correlation	7.6901	7.1688	-0.5213
22	50	Unbiased	7.532	7.1351	-0.3969
23	0	Correlation	7.3642	7.1142	-0.25
24	20	Biased	7.6077	7.1273	-0.4804
26	50	Biased	7.5775	7.1714	-0.4061
27	30	Unbiased	7.3754	7.1775	-0.1979
28	30	Biased	7.5042	7.1385	-0.3657
29	30	Unbiased	7.6734	7.0532	-0.6202
30	20	Biased	7.5729	6.8506	-0.7223
31	30	Unbiased	7.397	7.1536	-0.2434
33	30	Biased	7.7217	6.7876	-0.9341
34	50	Unbiased	7.4968	7.0347	-0.4621
35	20	Unbiased	7.352	6.7467	-0.6053
41	30	Biased	7.5109	7.0229	-0.488

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.3642	7.5781	7.7169	0.1622	6.8296	7.0709	7.1709	0.16298	-0.7116	-0.50723	-0.25	0.19117
20	7.352	7.5271	7.7084	0.12308	6.7467	7.0376	7.1817	0.16129	-0.7223	-0.48953	-0.2525	0.13489
30	7.3118	7.5046	7.7217	0.12733	6.7876	7.0245	7.1775	0.15553	-0.9341	-0.48008	-0.1979	0.22863
50	7.2926	7.5209	7.69	0.12074	6.8141	7.055	7.1714	0.13103	-0.8624	-0.46595	-0.1966	0.20319

Device Test: 24.19 TIMING|OUT_RISE/OUTH/5/12/0/1000/5/500kHz//@OUT_RISE_LDO





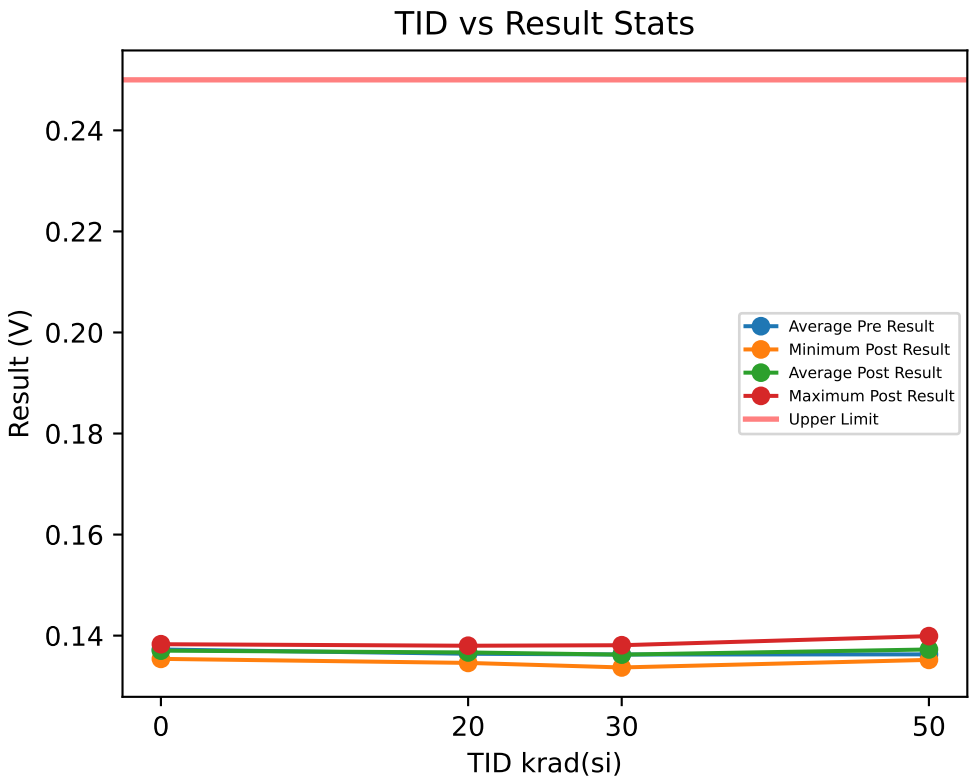
Test Results (Upper Limit = 16.0 (ns))

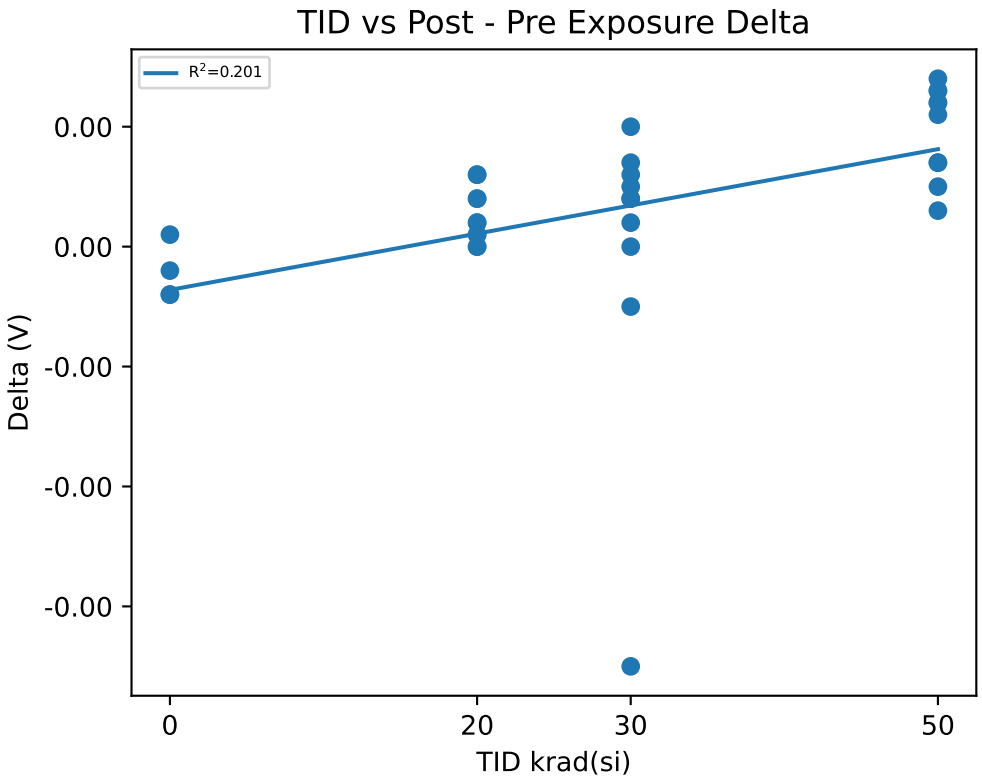
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	9.2588	8.9035	-0.3553
2	20	Unbiased	9.2178	8.9877	-0.2301
3	50	Biased	8.6247	8.7196	0.0949
4	30	Unbiased	8.9152	8.558	-0.3572
5	50	Unbiased	9.3352	8.5388	-0.7964
6	30	Biased	9.2689	8.3165	-0.9524
7	50	Biased	8.754	9.2359	0.4819
8	30	Unbiased	8.9333	9.0429	0.1096
9	20	Unbiased	9.2588	8.6073	-0.6515
10	50	Biased	9.2391	8.2588	-0.9803
11	30	Biased	8.6688	8.2252	-0.4436
12	0	Correlation	9.0482	8.4858	-0.5624
13	0	Correlation	9.2487	8.8788	-0.3699
14	50	Unbiased	9.3277	8.6666	-0.6611
15	20	Biased	8.8166	8.2956	-0.521
16	20	Unbiased	8.9162	9.0065	0.0903
17	20	Biased	9.3599	8.9467	-0.4132
18	20	Unbiased	9.3143	9.186	-0.1283
19	20	Biased	8.6849	9.0659	0.381
20	50	Unbiased	8.9562	8.687	-0.2692
21	0	Correlation	9.2945	9.0704	-0.2241
22	50	Unbiased	9.314	8.6544	-0.6596
23	0	Correlation	8.7559	9.1487	0.3928
24	20	Biased	8.9487	9.061	0.1123
26	50	Biased	9.385	8.9895	-0.3955
27	30	Unbiased	8.7847	8.6561	-0.1286
28	30	Biased	9.0195	9.0303	0.0108
29	30	Unbiased	9.2609	8.8337	-0.4272
30	20	Biased	9.3303	8.4374	-0.8929
31	30	Unbiased	8.7643	9.1584	0.3941
33	30	Biased	9.3211	8.2849	-1.0362
34	50	Unbiased	9.269	9.1747	-0.0943
35	20	Unbiased	8.7515	8.1149	-0.6366
41	30	Biased	8.9649	8.4459	-0.519

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	8.7559	9.0868	9.2945	0.24518	8.4858	8.8959	9.1487	0.29599	-0.5624	-0.1909	0.3928	0.41306
20	8.6849	9.0599	9.3599	0.26253	8.1149	8.7709	9.186	0.37582	-0.8929	-0.289	0.381	0.40405
30	8.6688	8.9902	9.3211	0.22788	8.2252	8.6552	9.1584	0.34417	-1.0362	-0.33497	0.3941	0.44956
50	8.6247	9.1464	9.385	0.26918	8.2588	8.7829	9.2359	0.29692	-0.9803	-0.36349	0.4819	0.44113

Device Test: 24.2 LEVEL|HIGH_LEVEL/OUTH/4.5/4.5/0/0/4.5/500kHz//@OUT_VOH





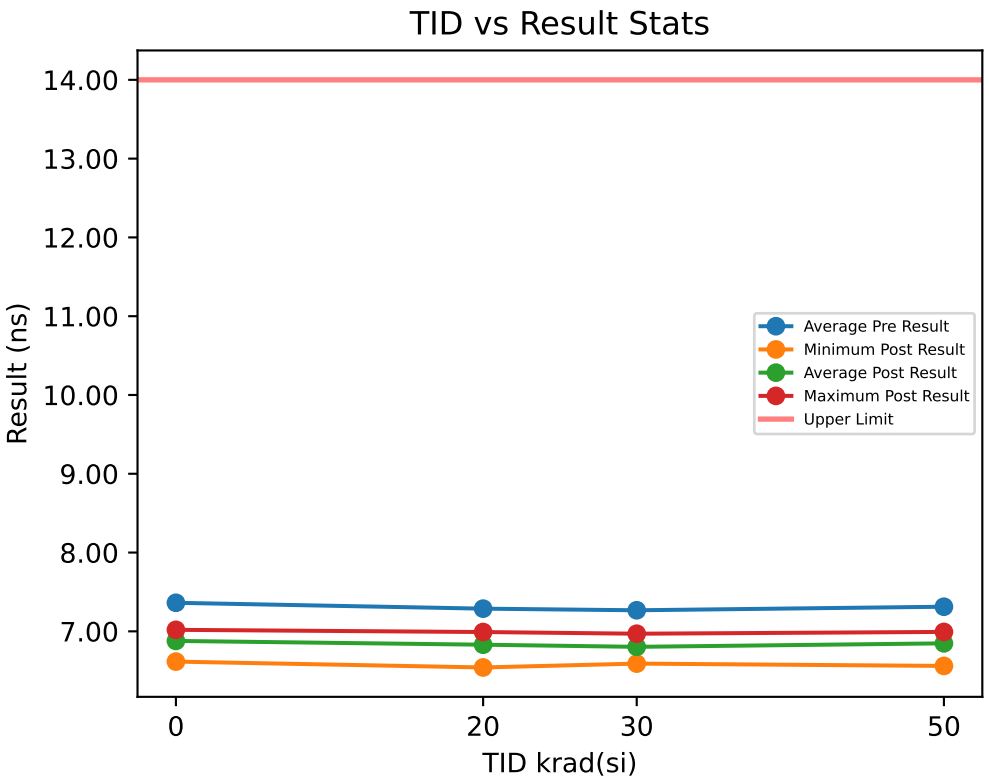
Test Results (Upper Limit = 0.25 (V))

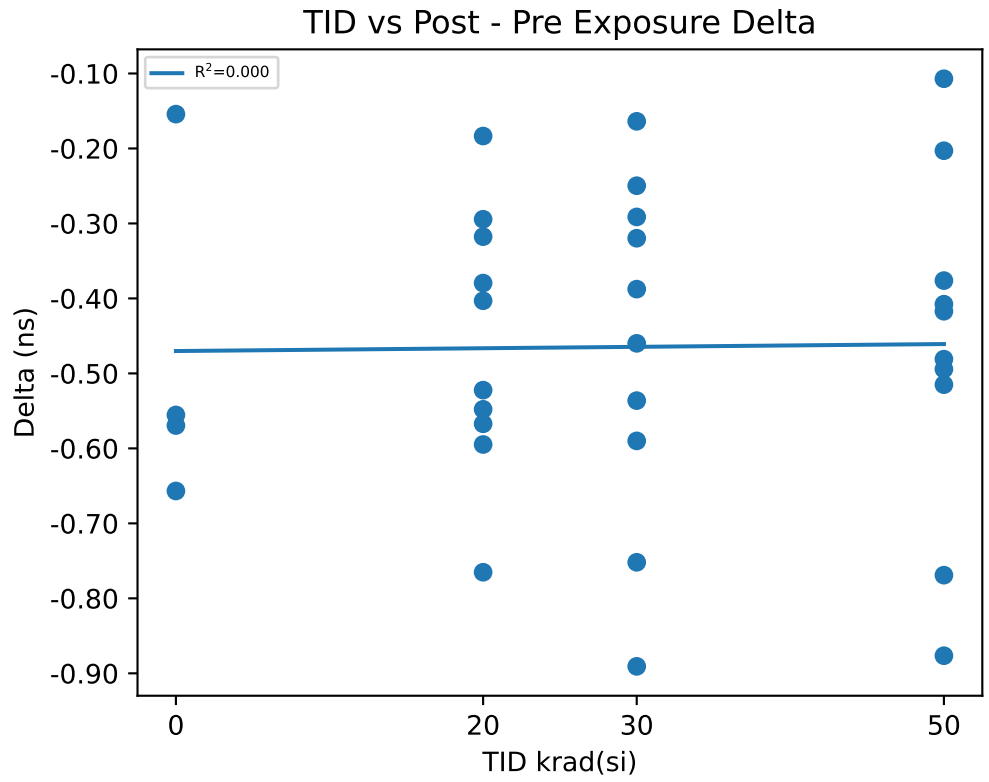
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	0.1341	0.1355	0.0014
2	20	Unbiased	0.1345	0.1349	0.0004
3	50	Biased	0.1344	0.1357	0.0013
4	30	Unbiased	0.134	0.1346	0.0006
5	50	Unbiased	0.1378	0.139	0.0012
6	30	Biased	0.1373	0.138	0.0007
7	50	Biased	0.1382	0.1395	0.0013
8	30	Unbiased	0.1341	0.1351	0.001
9	20	Unbiased	0.1352	0.1354	0.0002
10	50	Biased	0.1348	0.136	0.0012
11	30	Biased	0.1349	0.1354	0.0005
12	0	Correlation	0.1382	0.1383	0.0001
13	0	Correlation	0.1377	0.1373	-0.0004
14	50	Unbiased	0.1361	0.1366	0.0005
15	20	Biased	0.138	0.138	0
16	20	Unbiased	0.1369	0.1375	0.0006
17	20	Biased	0.1373	0.1379	0.0006
18	20	Unbiased	0.1379	0.138	0.0001
19	20	Biased	0.1348	0.135	0.0002
20	50	Unbiased	0.1392	0.1399	0.0007
21	0	Correlation	0.1356	0.1354	-0.0002
22	50	Unbiased	0.136	0.1363	0.0003
23	0	Correlation	0.1375	0.1371	-0.0004
24	20	Biased	0.1375	0.1379	0.0004
26	50	Biased	0.1378	0.1389	0.0011
27	30	Unbiased	0.1378	0.1378	0
28	30	Biased	0.1377	0.1381	0.0004
29	30	Unbiased	0.1348	0.135	0.0002
30	20	Biased	0.1374	0.1375	0.0001
31	30	Unbiased	0.1375	0.137	-0.0005
33	30	Biased	0.1373	0.1377	0.0004
34	50	Unbiased	0.1345	0.1352	0.0007
35	20	Unbiased	0.1346	0.1346	0
41	30	Biased	0.1372	0.1337	-0.0035

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.1356	0.13725	0.1382	0.0011387	0.1354	0.13703	0.1383	0.0012038	-0.0004	-0.000225	0.0001	0.00023629
20	0.1345	0.13641	0.138	0.0014502	0.1346	0.13667	0.138	0.0014818	0	0.00026	0.0006	0.00022706
30	0.134	0.13626	0.1378	0.0015911	0.1337	0.13624	0.1381	0.001646	-0.0035	-2e-05	0.001	0.0012891
50	0.1341	0.13629	0.1392	0.0018436	0.1352	0.13726	0.1399	0.0018386	0.0003	0.00097	0.0014	0.00038601

Device Test: 24.20 TIMING|OUT_FALL/OUTH/5/12/0/1000/5/500kHz//@OUT_FALL_LDO





Test Results (Upper Limit = 14.0 (ns))

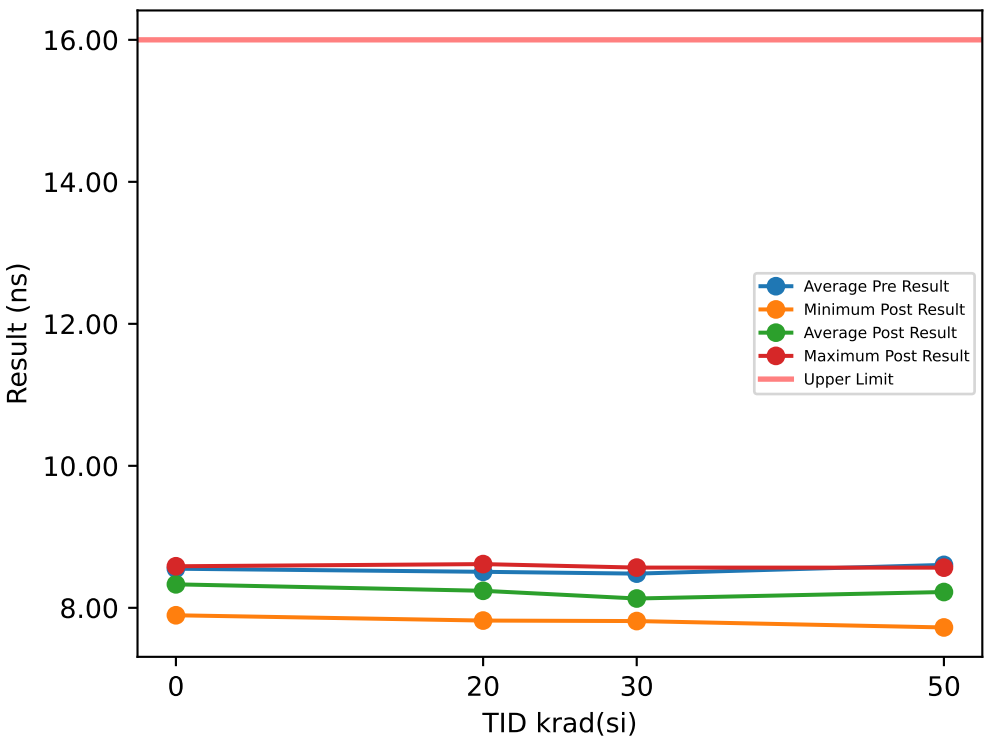
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	7.4702	6.9552	-0.515
2	20	Unbiased	7.3088	6.9293	-0.3795
3	50	Biased	7.0834	6.8804	-0.203
4	30	Unbiased	7.2052	6.8176	-0.3876
5	50	Unbiased	7.4924	6.6159	-0.8765
6	30	Biased	7.3549	6.603	-0.7519
7	50	Biased	7.0996	6.9926	-0.107
8	30	Unbiased	7.244	6.9243	-0.3197
9	20	Unbiased	7.4727	6.8779	-0.5948
10	50	Biased	7.3302	6.5611	-0.7691
11	30	Biased	7.0505	6.5906	-0.4599
12	0	Correlation	7.2728	6.616	-0.6568
13	0	Correlation	7.5118	6.9564	-0.5554
14	50	Unbiased	7.3589	6.8779	-0.481
15	20	Biased	7.1268	6.5789	-0.5479
16	20	Unbiased	7.2608	6.9432	-0.3176
17	20	Biased	7.5136	6.9913	-0.5223
18	20	Unbiased	7.362	6.9589	-0.4031
19	20	Biased	7.0766	6.8932	-0.1834
20	50	Unbiased	7.2503	6.8741	-0.3762
21	0	Correlation	7.4913	6.9218	-0.5695
22	50	Unbiased	7.3587	6.8644	-0.4943
23	0	Correlation	7.1734	7.0192	-0.1542
24	20	Biased	7.2684	6.974	-0.2944
26	50	Biased	7.391	6.9739	-0.4171
27	30	Unbiased	7.1481	6.8984	-0.2497
28	30	Biased	7.2591	6.9678	-0.2913
29	30	Unbiased	7.4779	6.8879	-0.59
30	20	Biased	7.3808	6.6156	-0.7652
31	30	Unbiased	7.1337	6.9699	-0.1638
33	30	Biased	7.4966	6.6059	-0.8907
34	50	Unbiased	7.289	6.8813	-0.4077
35	20	Unbiased	7.1088	6.5416	-0.5672
41	30	Biased	7.3038	6.7675	-0.5363

Test Statistics (ns)

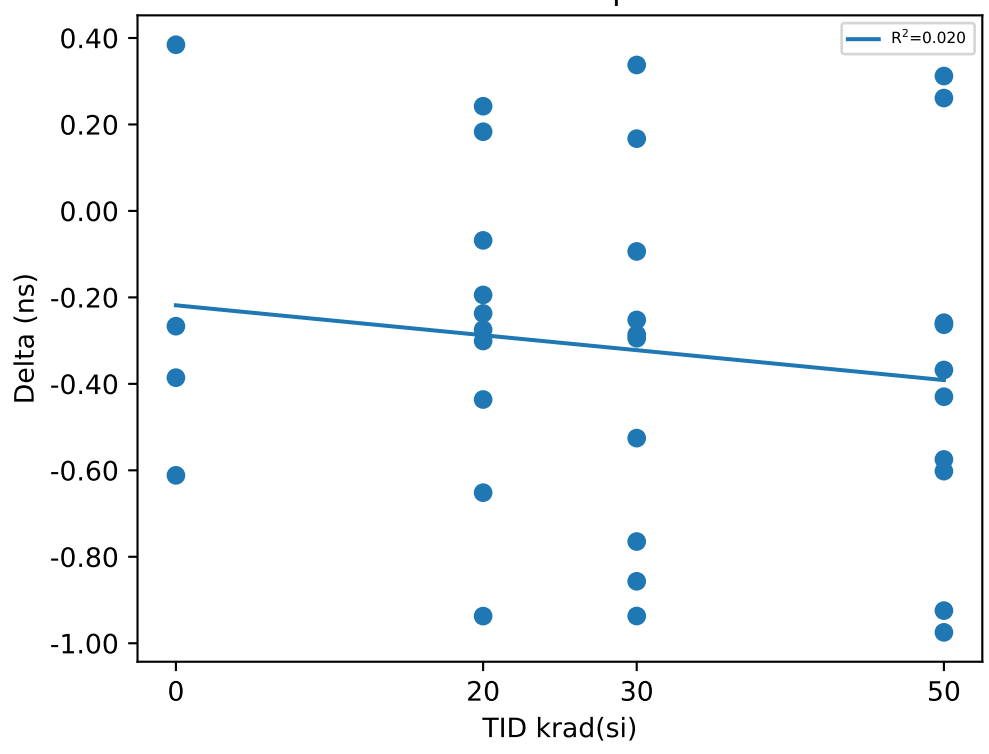
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.1734	7.3623	7.5118	0.16602	6.616	6.8784	7.0192	0.17949	-0.6568	-0.48398	-0.1542	0.22438
20	7.0766	7.2879	7.5136	0.15035	6.5416	6.8304	6.9913	0.1778	-0.7652	-0.45754	-0.1834	0.17265
30	7.0505	7.2674	7.4966	0.14509	6.5906	6.8033	6.9699	0.15329	-0.8907	-0.46409	-0.1638	0.23061
50	7.0834	7.3124	7.4924	0.13753	6.5611	6.8477	6.9926	0.1447	-0.8765	-0.46469	-0.107	0.2299

Device Test: 24.21 TIMING|OUT_RISE/OUTH/5.5/12/0/1000/5.5/500kHz//@OUT_RISE_LDO

TID vs Result Stats



TID vs Post - Pre Exposure Delta



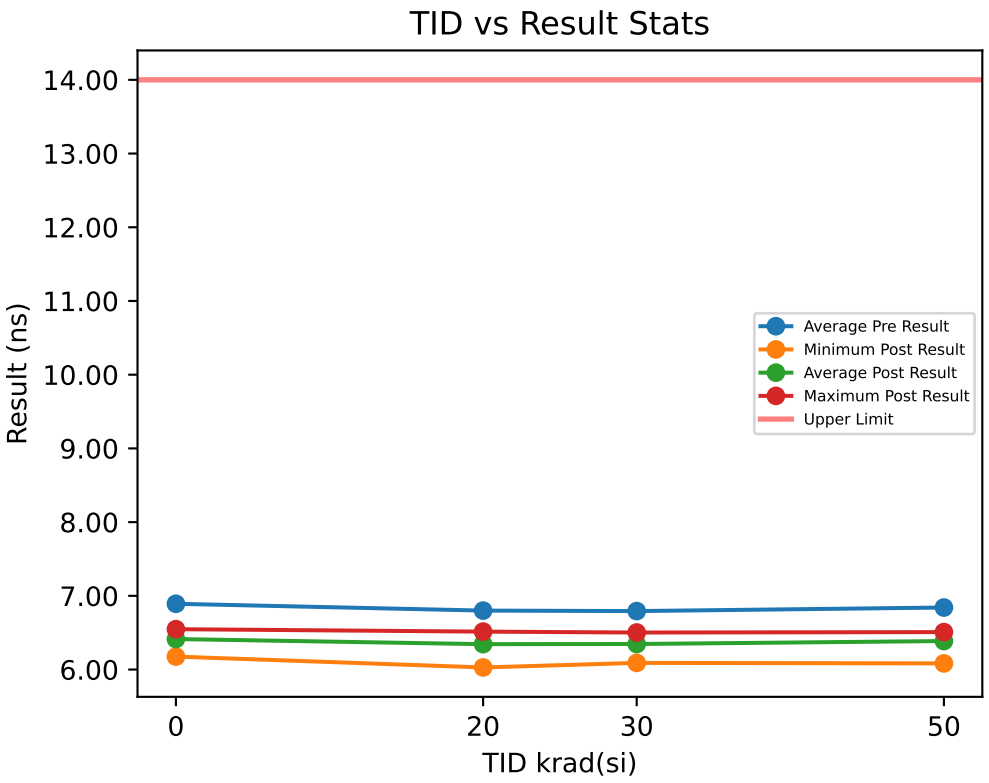
Test Results (Upper Limit = 16.0 (ns))

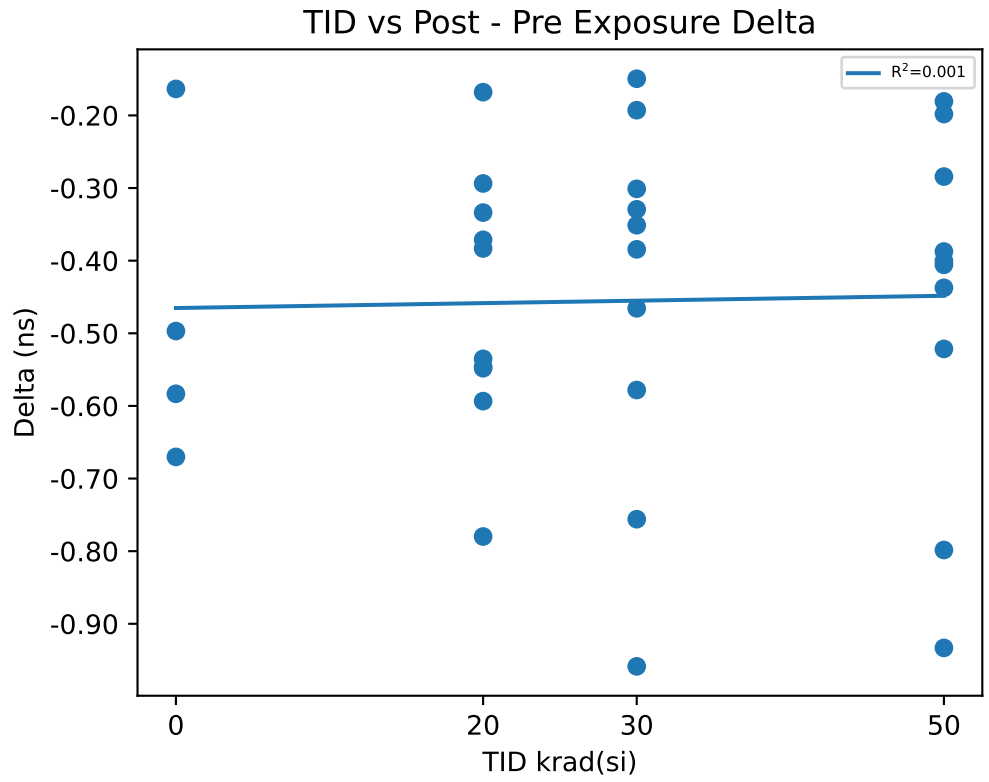
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	8.6998	8.27	-0.4298
2	20	Unbiased	8.7279	8.4533	-0.2746
3	50	Biased	8.1708	8.4828	0.312
4	30	Unbiased	8.3923	7.8668	-0.5255
5	50	Unbiased	8.8874	7.9126	-0.9748
6	30	Biased	8.748	7.9833	-0.7647
7	50	Biased	8.1935	8.4546	0.2611
8	30	Unbiased	8.3996	8.5668	0.1672
9	20	Unbiased	8.6947	8.043	-0.6517
10	50	Biased	8.648	7.7235	-0.9245
11	30	Biased	8.1157	7.8212	-0.2945
12	0	Correlation	8.5067	7.8951	-0.6116
13	0	Correlation	8.7831	8.3974	-0.3857
14	50	Unbiased	8.7466	8.1447	-0.6019
15	20	Biased	8.2568	7.8206	-0.4362
16	20	Unbiased	8.4327	8.6159	0.1832
17	20	Biased	8.7571	8.4562	-0.3009
18	20	Unbiased	8.7457	8.5086	-0.2371
19	20	Biased	8.1255	8.3677	0.2422
20	50	Unbiased	8.4455	8.1823	-0.2632
21	0	Correlation	8.712	8.4454	-0.2666
22	50	Unbiased	8.7457	8.1709	-0.5748
23	0	Correlation	8.201	8.5854	0.3844
24	20	Biased	8.4728	8.4047	-0.0681
26	50	Biased	8.8244	8.5659	-0.2585
27	30	Unbiased	8.2452	7.9931	-0.2521
28	30	Biased	8.4724	8.3787	-0.0937
29	30	Unbiased	8.7228	8.4368	-0.286
30	20	Biased	8.7669	7.8297	-0.9372
31	30	Unbiased	8.1972	8.5348	0.3376
33	30	Biased	8.7506	7.8136	-0.937
34	50	Unbiased	8.6862	8.3183	-0.3679
35	20	Unbiased	8.0936	7.8993	-0.1943
41	30	Biased	8.7745	7.9178	-0.8567

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	8.201	8.5507	8.7831	0.26093	7.8951	8.3308	8.5854	0.30123	-0.6116	-0.21988	0.3844	0.4275
20	8.0936	8.5074	8.7669	0.27015	7.8206	8.2399	8.6159	0.307	-0.9372	-0.26747	0.2422	0.35507
30	8.1157	8.4818	8.7745	0.25226	7.8136	8.1313	8.5668	0.30924	-0.937	-0.35054	0.3376	0.42516
50	8.1708	8.6048	8.8874	0.25132	7.7235	8.2226	8.5659	0.25956	-0.9748	-0.38223	0.312	0.42925

Device Test: 24.22 TIMING|OUT_FALL/OUTH/5.5/12/0/1000/5.5/500kHz//@OUT_FALL_LDO





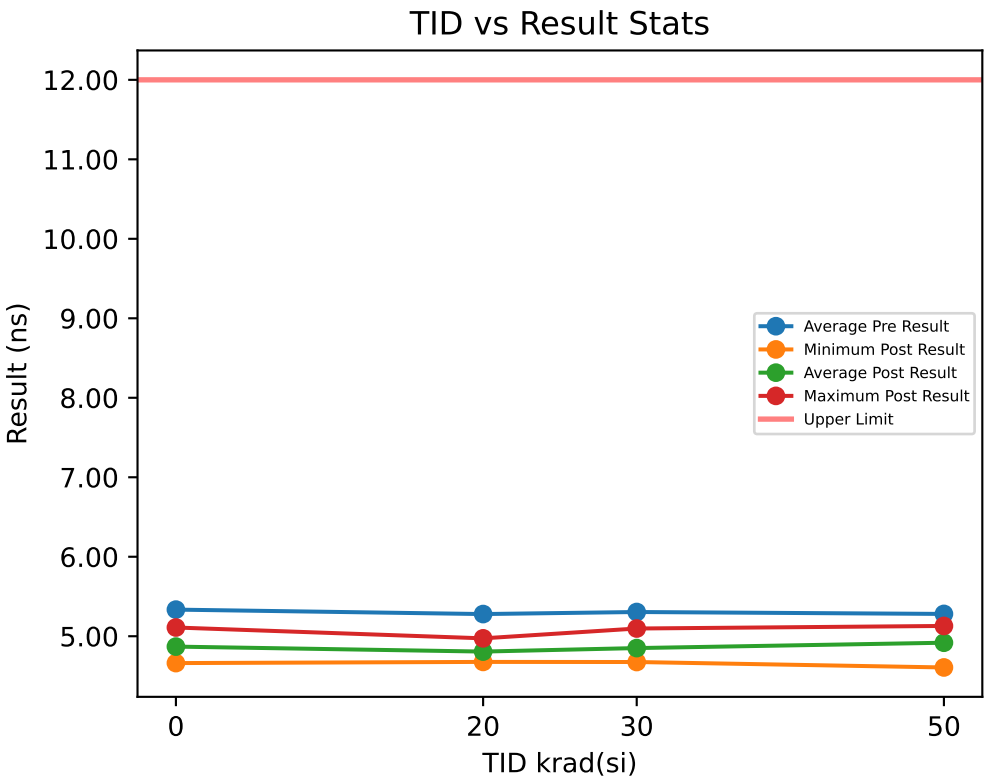
Test Results (Upper Limit = 14.0 (ns))

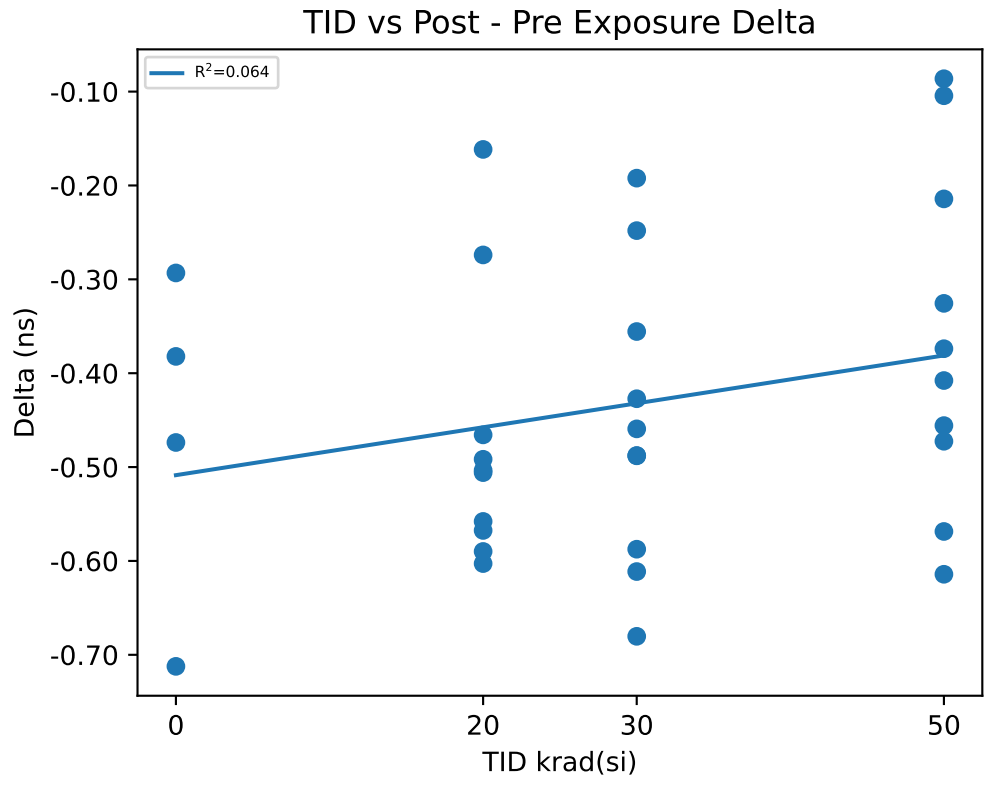
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	6.9893	6.4678	-0.5215
2	20	Unbiased	6.8119	6.4406	-0.3713
3	50	Biased	6.6242	6.4261	-0.1981
4	30	Unbiased	6.7606	6.4094	-0.3512
5	50	Unbiased	7.0453	6.1121	-0.9332
6	30	Biased	6.8841	6.1281	-0.756
7	50	Biased	6.6707	6.49	-0.1807
8	30	Unbiased	6.7929	6.4636	-0.3293
9	20	Unbiased	7.0014	6.4533	-0.5481
10	50	Biased	6.8819	6.0835	-0.7984
11	30	Biased	6.5596	6.094	-0.4656
12	0	Correlation	6.8462	6.176	-0.6702
13	0	Correlation	7.0445	6.5476	-0.4969
14	50	Unbiased	6.8742	6.4368	-0.4374
15	20	Biased	6.6063	6.0711	-0.5352
16	20	Unbiased	6.7866	6.4528	-0.3338
17	20	Biased	7.0484	6.455	-0.5934
18	20	Unbiased	6.8789	6.4957	-0.3832
19	20	Biased	6.5975	6.4295	-0.168
20	50	Unbiased	6.7726	6.4884	-0.2842
21	0	Correlation	7.0136	6.4303	-0.5833
22	50	Unbiased	6.8534	6.466	-0.3874
23	0	Correlation	6.6644	6.5009	-0.1635
24	20	Biased	6.8082	6.5145	-0.2937
26	50	Biased	6.9136	6.5079	-0.4057
27	30	Unbiased	6.6635	6.4707	-0.1928
28	30	Biased	6.8033	6.5022	-0.3011
29	30	Unbiased	7.0194	6.4413	-0.5781
30	20	Biased	6.8849	6.1051	-0.7798
31	30	Unbiased	6.642	6.4925	-0.1495
33	30	Biased	7.0489	6.0903	-0.9586
34	50	Unbiased	6.7882	6.3879	-0.4003
35	20	Unbiased	6.5744	6.0284	-0.546
41	30	Biased	6.7584	6.374	-0.3844

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.6644	6.8922	7.0445	0.17506	6.176	6.4137	6.5476	0.16564	-0.6702	-0.47847	-0.1635	0.22158
20	6.5744	6.7999	7.0484	0.16516	6.0284	6.3446	6.5145	0.19321	-0.7798	-0.45525	-0.168	0.17741
30	6.5596	6.7933	7.0489	0.15686	6.0903	6.3466	6.5022	0.17175	-0.9586	-0.44666	-0.1495	0.25301
50	6.6242	6.8413	7.0453	0.1314	6.0835	6.3867	6.5079	0.15634	-0.9332	-0.45469	-0.1807	0.24307

Device Test: 24.23 TIMING|OUT_RISE/OUTH/4.5/12/0/220/4.5/500kHz//@OUT_RISE_220PF





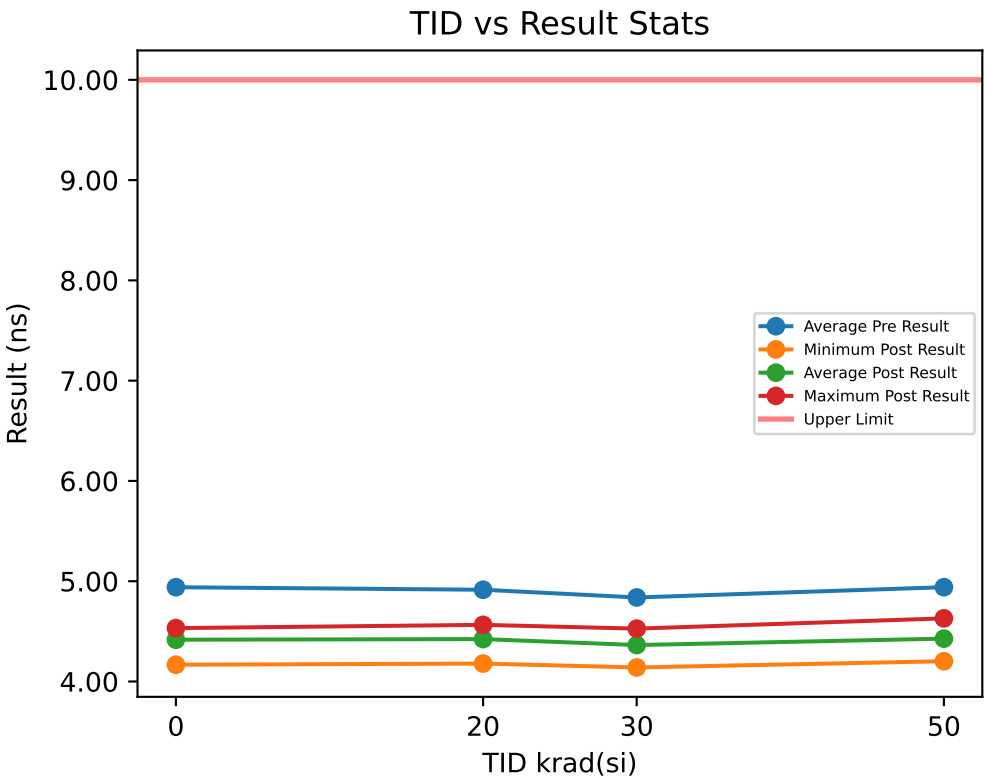
Test Results (Upper Limit = 12.0 (ns))

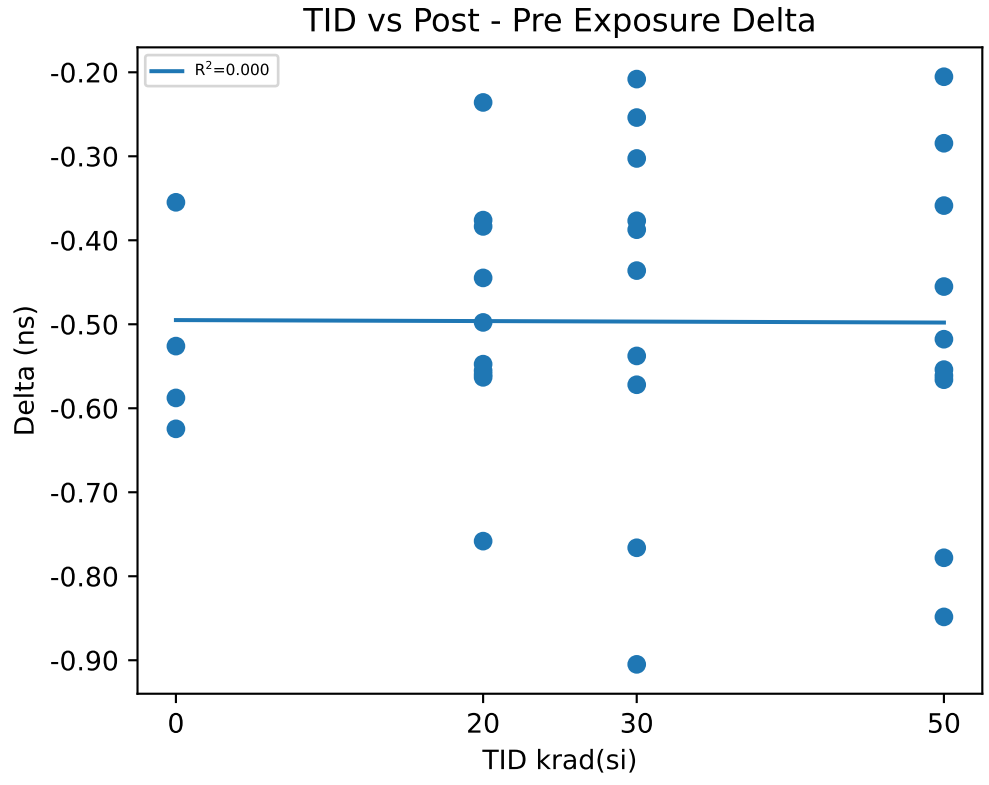
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	5.4228	5.015	-0.4078
2	20	Unbiased	5.1351	4.9735	-0.1616
3	50	Biased	5.155	4.9407	-0.2143
4	30	Unbiased	5.3142	4.887	-0.4272
5	50	Unbiased	5.477	4.8628	-0.6142
6	30	Biased	5.2268	4.7388	-0.488
7	50	Biased	5.2157	5.1294	-0.0863
8	30	Unbiased	5.356	4.6757	-0.6803
9	20	Unbiased	5.4207	4.929	-0.4917
10	50	Biased	5.1758	4.6072	-0.5686
11	30	Biased	5.2205	4.7612	-0.4593
12	0	Correlation	5.3824	4.9086	-0.4738
13	0	Correlation	5.403	5.1098	-0.2932
14	50	Unbiased	5.2456	4.92	-0.3256
15	20	Biased	5.2669	4.677	-0.5899
16	20	Unbiased	5.3475	4.7447	-0.6028
17	20	Biased	5.4182	4.8507	-0.5675
18	20	Unbiased	5.2606	4.7572	-0.5034
19	20	Biased	5.2112	4.9372	-0.274
20	50	Unbiased	5.3492	4.8767	-0.4725
21	0	Correlation	5.3745	4.6622	-0.7123
22	50	Unbiased	5.3129	4.8571	-0.4558
23	0	Correlation	5.1795	4.7974	-0.3821
24	20	Biased	5.3419	4.784	-0.5579
26	50	Biased	5.2551	4.8812	-0.3739
27	30	Unbiased	5.2263	5.0341	-0.1922
28	30	Biased	5.3452	5.0971	-0.2481
29	30	Unbiased	5.4028	4.8153	-0.5875
30	20	Biased	5.1936	4.7279	-0.4657
31	30	Unbiased	5.2137	4.8581	-0.3556
33	30	Biased	5.4725	4.8612	-0.6113
34	50	Unbiased	5.198	5.0936	-0.1044
35	20	Unbiased	5.1946	4.6887	-0.5059
41	30	Biased	5.2695	4.7818	-0.4877

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.1795	5.3348	5.403	0.10426	4.6622	4.8695	5.1098	0.18925	-0.7123	-0.46535	-0.2932	0.18039
20	5.1351	5.279	5.4207	0.099057	4.677	4.807	4.9735	0.10827	-0.6028	-0.47204	-0.1616	0.14361
30	5.2137	5.3048	5.4725	0.088799	4.6757	4.851	5.0971	0.13038	-0.6803	-0.45372	-0.1922	0.15543
50	5.155	5.2807	5.477	0.10761	4.6072	4.9184	5.1294	0.14601	-0.6142	-0.36234	-0.0863	0.18106

Device Test: 24.24 TIMING|OUT_FALL/OUTH/4.5/12/0/220/4.5/500kHz//@OUT_FALL_220PF





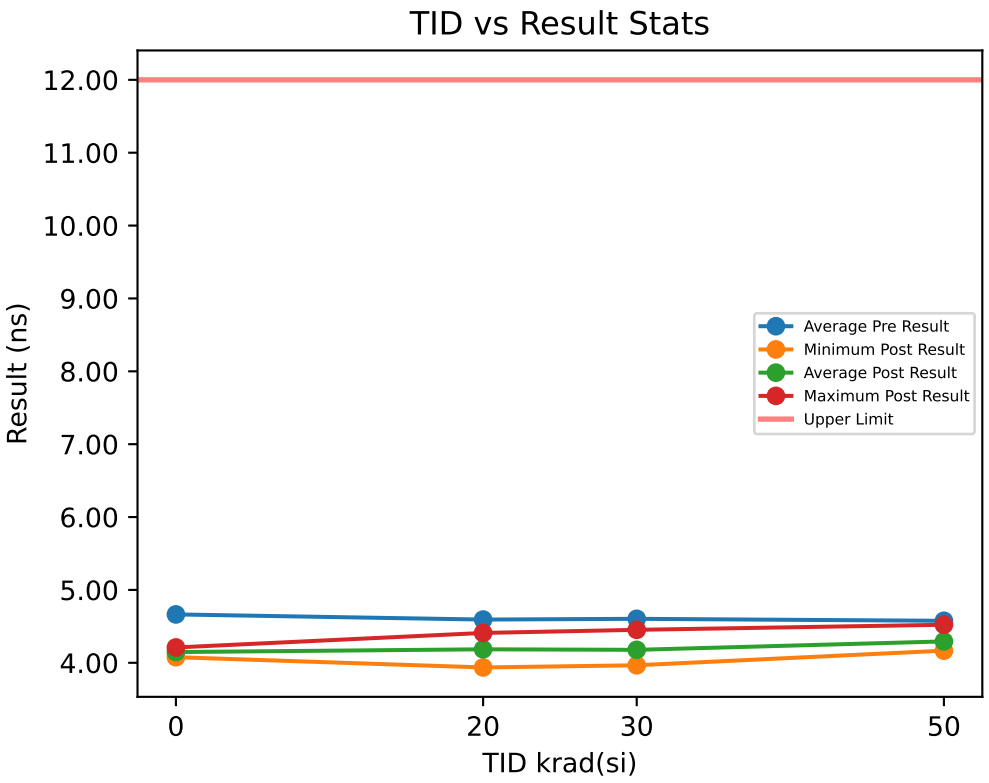
Test Results (Upper Limit = 10.0 (ns))

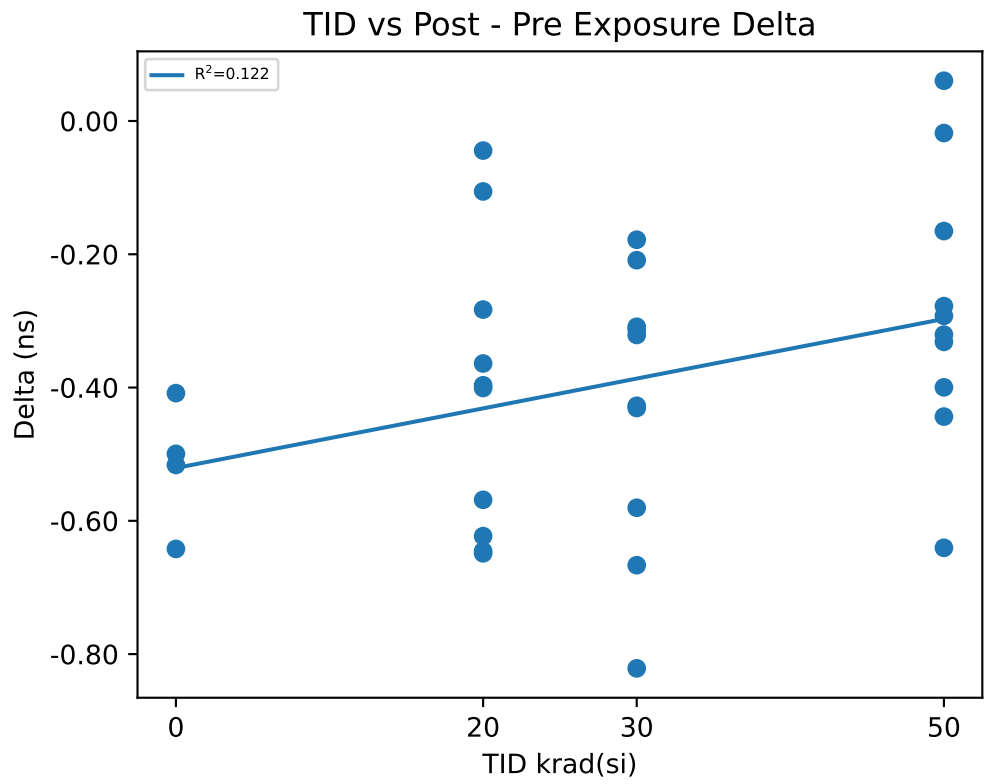
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	5.0706	4.5046	-0.566
2	20	Unbiased	5.0265	4.5287	-0.4978
3	50	Biased	4.8535	4.569	-0.2845
4	30	Unbiased	4.9146	4.5272	-0.3874
5	50	Unbiased	5.0505	4.2021	-0.8484
6	30	Biased	4.911	4.1449	-0.7661
7	50	Biased	4.6562	4.4509	-0.2053
8	30	Unbiased	4.8105	4.5079	-0.3026
9	20	Unbiased	5.1007	4.5455	-0.5552
10	50	Biased	4.9826	4.2046	-0.778
11	30	Biased	4.7466	4.2089	-0.5377
12	0	Correlation	4.7916	4.1671	-0.6245
13	0	Correlation	5.0481	4.5221	-0.526
14	50	Unbiased	4.9699	4.4159	-0.554
15	20	Biased	4.742	4.1788	-0.5632
16	20	Unbiased	4.8756	4.4921	-0.3835
17	20	Biased	5.0591	4.4993	-0.5598
18	20	Unbiased	4.9638	4.519	-0.4448
19	20	Biased	4.8008	4.5649	-0.2359
20	50	Unbiased	4.8117	4.453	-0.3587
21	0	Correlation	5.1202	4.5325	-0.5877
22	50	Unbiased	4.9883	4.4271	-0.5612
23	0	Correlation	4.8003	4.4455	-0.3548
24	20	Biased	4.7819	4.4059	-0.376
26	50	Biased	4.9355	4.4177	-0.5178
27	30	Unbiased	4.7002	4.4463	-0.2539
28	30	Biased	4.7859	4.4091	-0.3768
29	30	Unbiased	5.0637	4.4917	-0.572
30	20	Biased	4.9404	4.1822	-0.7582
31	30	Unbiased	4.7109	4.5028	-0.2081
33	30	Biased	5.0449	4.14	-0.9049
34	50	Unbiased	5.0847	4.6296	-0.4551
35	20	Unbiased	4.8595	4.312	-0.5475
41	30	Biased	4.6921	4.256	-0.4361

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.7916	4.94	5.1202	0.16901	4.1671	4.4168	4.5325	0.17093	-0.6245	-0.52325	-0.3548	0.11943
20	4.742	4.915	5.1007	0.12294	4.1788	4.4228	4.5649	0.14771	-0.7582	-0.49219	-0.2359	0.14169
30	4.6921	4.838	5.0637	0.13872	4.14	4.3635	4.5272	0.15833	-0.9049	-0.47456	-0.2081	0.224
50	4.6562	4.9404	5.0847	0.13323	4.2021	4.4275	4.6296	0.13692	-0.8484	-0.5129	-0.2053	0.201

Device Test: 24.25 TIMING|OUT_RISE/OUTH/5/12/0/220/5/500kHz//@OUT_RISE_220PF





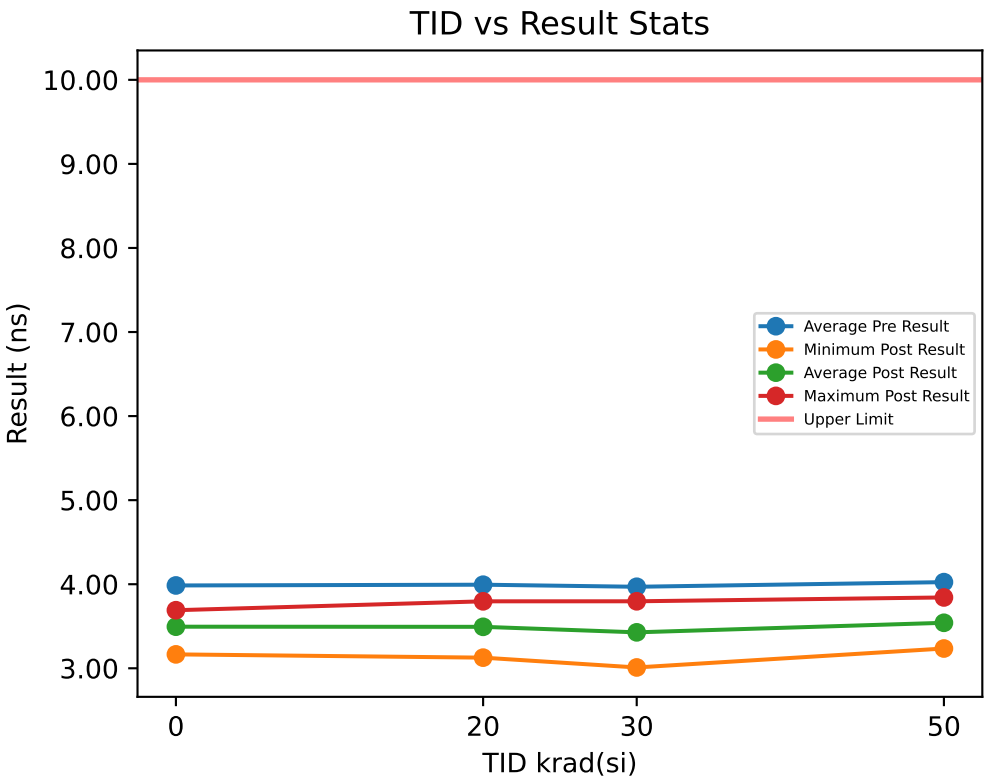
Test Results (Upper Limit = 12.0 (ns))

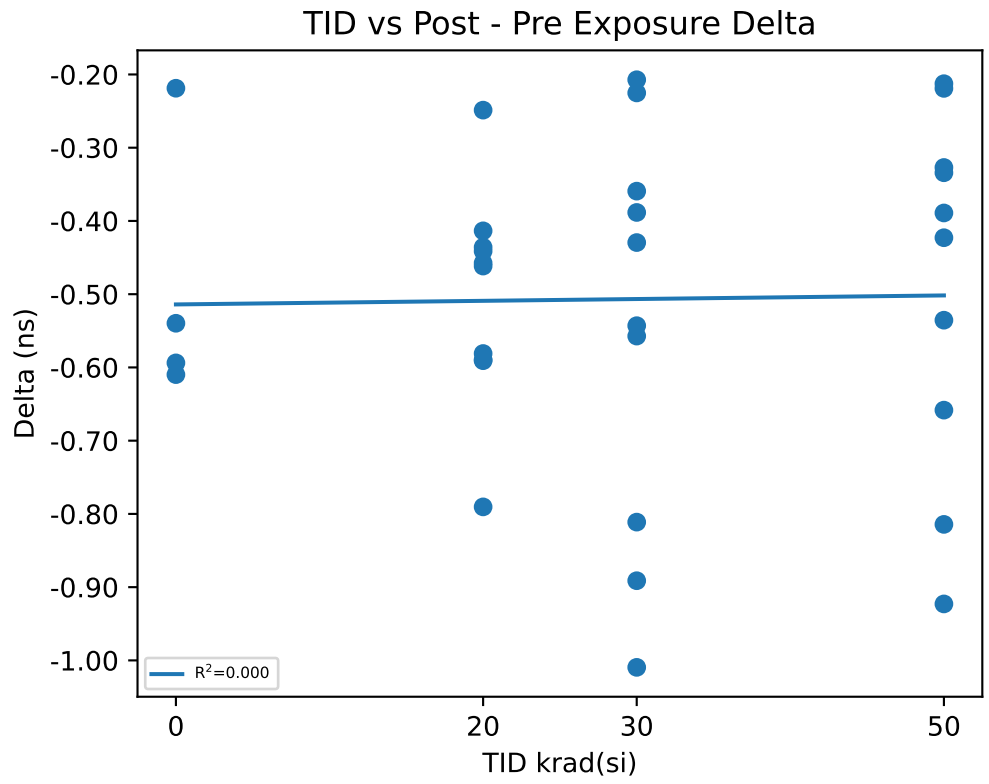
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	4.6972	4.2536	-0.4436
2	20	Unbiased	4.5006	4.3949	-0.1057
3	50	Biased	4.4189	4.4008	-0.0181
4	30	Unbiased	4.6192	4.1885	-0.4307
5	50	Unbiased	4.8071	4.1666	-0.6405
6	30	Biased	4.5747	3.9943	-0.5804
7	50	Biased	4.5353	4.2575	-0.2778
8	30	Unbiased	4.6732	4.0066	-0.6666
9	20	Unbiased	4.7648	4.3641	-0.4007
10	50	Biased	4.5149	4.1943	-0.3206
11	30	Biased	4.4704	4.043	-0.4274
12	0	Correlation	4.7191	4.0769	-0.6422
13	0	Correlation	4.7265	4.2103	-0.5162
14	50	Unbiased	4.4805	4.1881	-0.2924
15	20	Biased	4.5238	4.1272	-0.3966
16	20	Unbiased	4.6621	4.0936	-0.5685
17	20	Biased	4.7676	4.1446	-0.623
18	20	Unbiased	4.5352	4.2522	-0.283
19	20	Biased	4.4541	4.4097	-0.0444
20	50	Unbiased	4.7115	4.38	-0.3315
21	0	Correlation	4.7029	4.2034	-0.4995
22	50	Unbiased	4.5366	4.3714	-0.1652
23	0	Correlation	4.507	4.0986	-0.4084
24	20	Biased	4.7117	4.0663	-0.6454
26	50	Biased	4.6001	4.2004	-0.3997
27	30	Unbiased	4.5637	4.2549	-0.3088
28	30	Biased	4.6613	4.4524	-0.2089
29	30	Unbiased	4.7477	4.4347	-0.313
30	20	Biased	4.5848	3.936	-0.6488
31	30	Unbiased	4.5498	4.2287	-0.3211
33	30	Biased	4.7874	3.966	-0.8214
34	50	Unbiased	4.4615	4.5219	0.0604
35	20	Unbiased	4.4268	4.0629	-0.3639
41	30	Biased	4.3872	4.209	-0.1782

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.507	4.6639	4.7265	0.10505	4.0769	4.1473	4.2103	0.069388	-0.6422	-0.51657	-0.4084	0.096221
20	4.4268	4.5931	4.7676	0.12584	3.936	4.1852	4.4097	0.16175	-0.6488	-0.408	-0.0444	0.21799
30	4.3872	4.6035	4.7874	0.1215	3.966	4.1778	4.4524	0.17545	-0.8214	-0.42565	-0.1782	0.2066
50	4.4189	4.5764	4.8071	0.12512	4.1666	4.2935	4.5219	0.11825	-0.6405	-0.2829	0.0604	0.2036

Device Test: 24.26 TIMING|OUT_FALL/OUTH/5/12/0/220/5/500kHz//@OUT_FALL_220PF





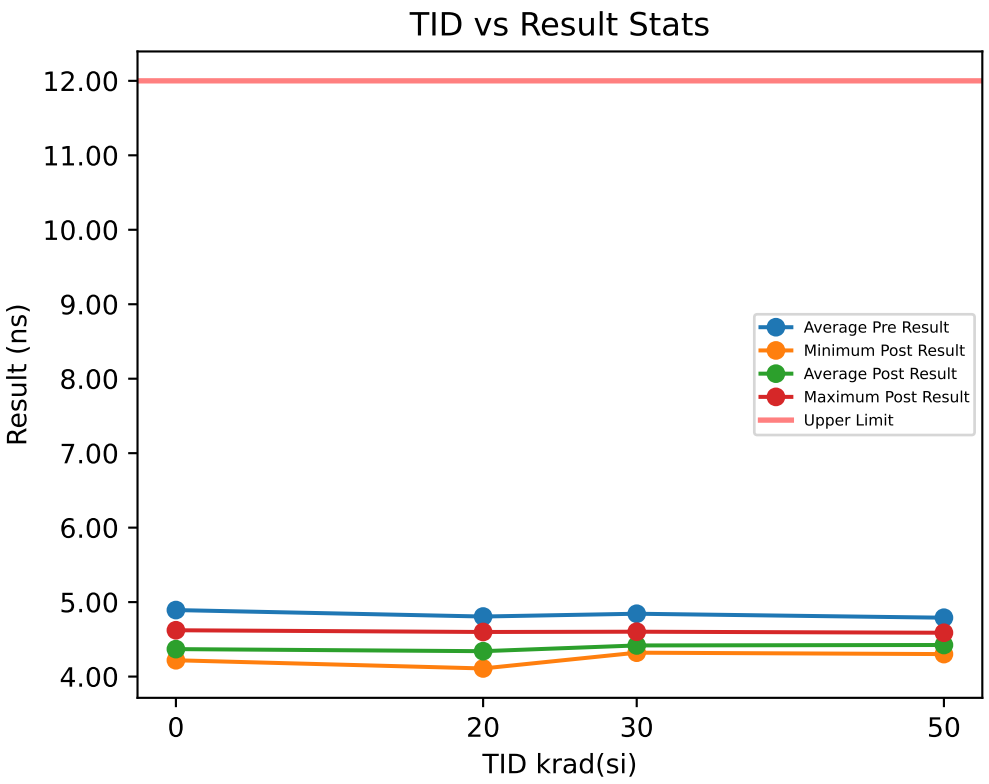
Test Results (Upper Limit = 10.0 (ns))

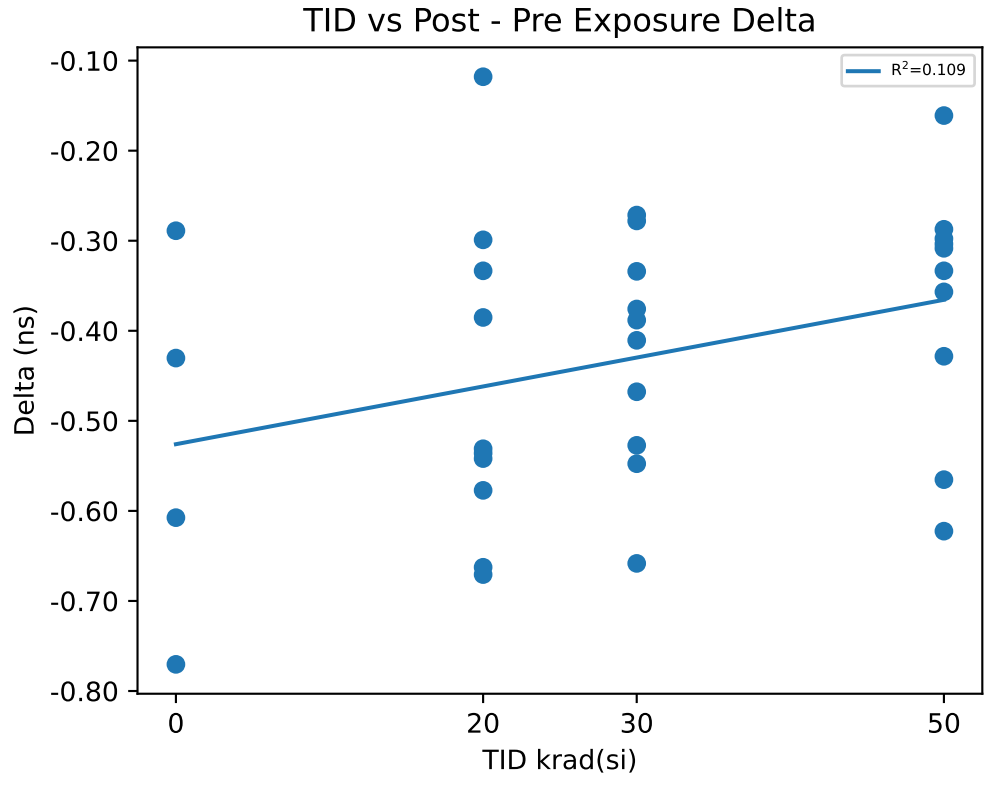
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	4.2676	3.6093	-0.6583
2	20	Unbiased	4.1091	3.6732	-0.4359
3	50	Biased	3.9477	3.7351	-0.2126
4	30	Unbiased	4.1562	3.7969	-0.3593
5	50	Unbiased	4.1581	3.2352	-0.9229
6	30	Biased	3.9529	3.1417	-0.8112
7	50	Biased	3.691	3.472	-0.219
8	30	Unbiased	4.0255	3.6371	-0.3884
9	20	Unbiased	4.2581	3.7965	-0.4616
10	50	Biased	4.0529	3.2386	-0.8143
11	30	Biased	3.8917	3.3487	-0.543
12	0	Correlation	3.7752	3.1654	-0.6098
13	0	Correlation	4.1569	3.6172	-0.5397
14	50	Unbiased	4.0655	3.6426	-0.4229
15	20	Biased	3.7486	3.1676	-0.581
16	20	Unbiased	3.9908	3.5773	-0.4135
17	20	Biased	4.1327	3.5432	-0.5895
18	20	Unbiased	3.9441	3.5029	-0.4412
19	20	Biased	3.9783	3.7296	-0.2487
20	50	Unbiased	3.888	3.5538	-0.3342
21	0	Correlation	4.2845	3.6907	-0.5938
22	50	Unbiased	4.048	3.721	-0.327
23	0	Correlation	3.7245	3.5057	-0.2188
24	20	Biased	3.8848	3.4274	-0.4574
26	50	Biased	3.8968	3.3613	-0.5355
27	30	Unbiased	3.6481	3.4409	-0.2072
28	30	Biased	3.9077	3.4782	-0.4295
29	30	Unbiased	4.2371	3.6799	-0.5572
30	20	Biased	3.9169	3.1265	-0.7904
31	30	Unbiased	3.7764	3.5512	-0.2252
33	30	Biased	4.2	3.1905	-1.0095
34	50	Unbiased	4.2317	3.8426	-0.3891
35	20	Unbiased	3.9784	3.3876	-0.5908
41	30	Biased	3.901	3.0098	-0.8912

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.7245	3.9853	4.2845	0.27756	3.1654	3.4947	3.6907	0.23237	-0.6098	-0.49053	-0.2188	0.18362
20	3.7486	3.9942	4.2581	0.14272	3.1265	3.4932	3.7965	0.22259	-0.7904	-0.501	-0.2487	0.14477
30	3.6481	3.9697	4.2371	0.18802	3.0098	3.4275	3.7969	0.25401	-1.0095	-0.54217	-0.2072	0.27794
50	3.691	4.0247	4.2676	0.17479	3.2352	3.5411	3.8426	0.21034	-0.9229	-0.48358	-0.2126	0.2446

Device Test: 24.27 TIMING|OUT_RISE/OUTH/5.5/12/0/220/5.5/500kHz//@OUT_RISE_220PF





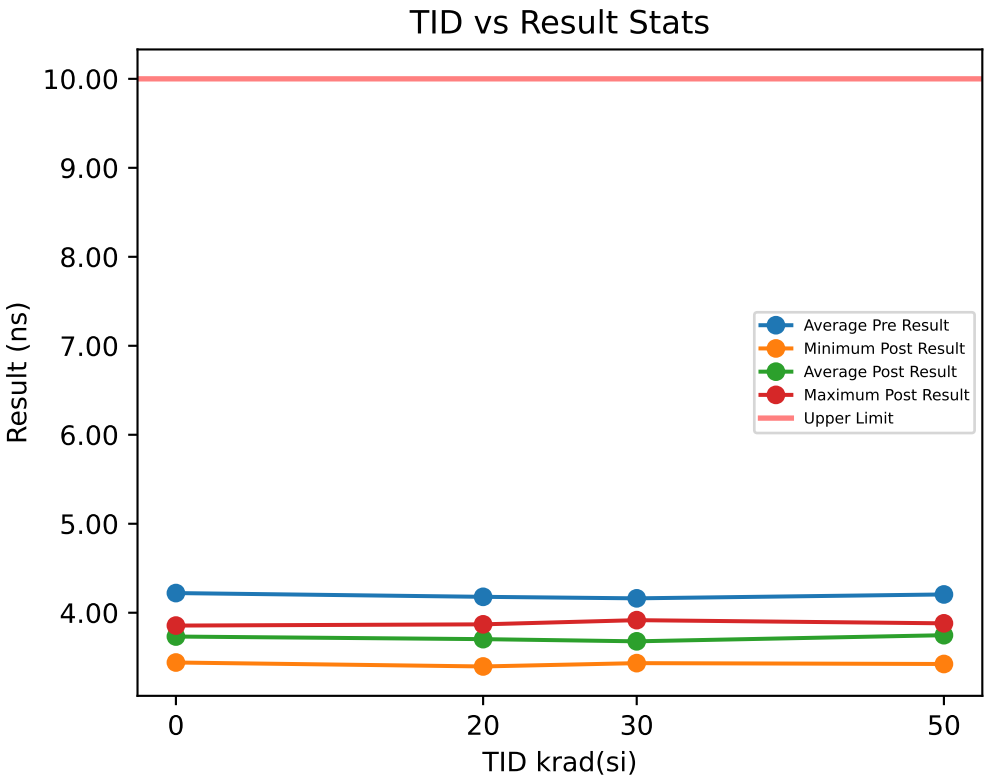
Test Results (Upper Limit = 12.0 (ns))

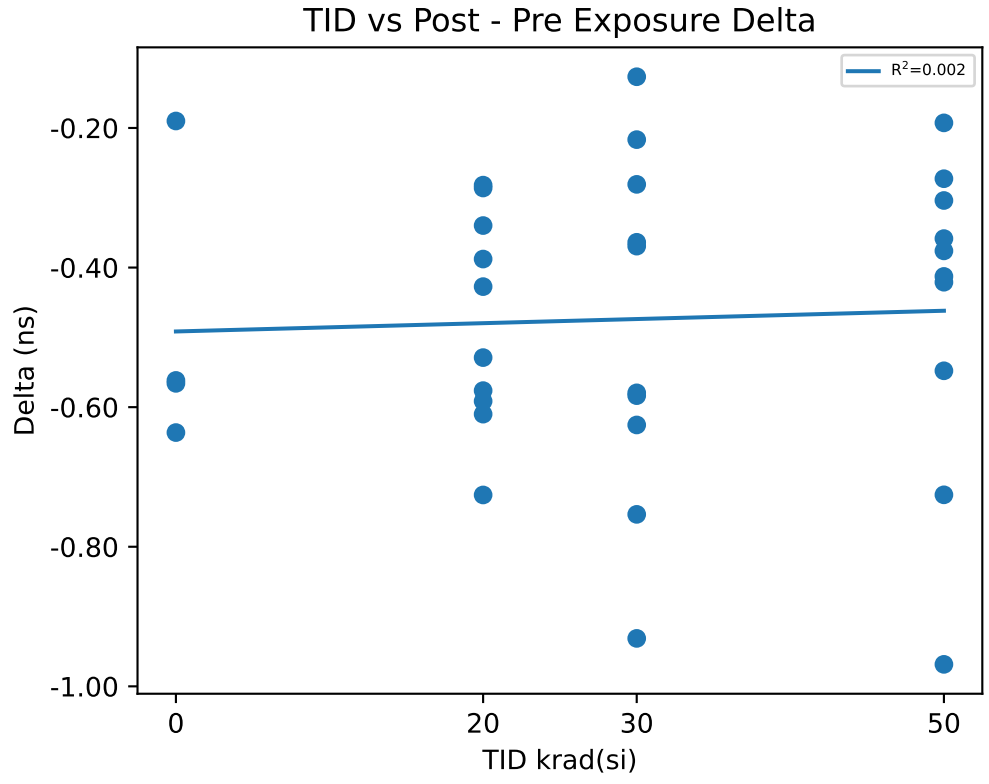
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	4.9219	4.5885	-0.3334
2	20	Unbiased	4.6891	4.5712	-0.1179
3	50	Biased	4.6262	4.4652	-0.161
4	30	Unbiased	4.8805	4.6025	-0.278
5	50	Unbiased	5.0301	4.4076	-0.6225
6	30	Biased	4.7592	4.3834	-0.3758
7	50	Biased	4.7199	4.4326	-0.2873
8	30	Unbiased	4.9231	4.3755	-0.5476
9	20	Unbiased	4.9323	4.5989	-0.3334
10	50	Biased	4.7303	4.302	-0.4283
11	30	Biased	4.6714	4.3999	-0.2715
12	0	Correlation	4.9894	4.219	-0.7704
13	0	Correlation	4.9109	4.622	-0.2889
14	50	Unbiased	4.781	4.4726	-0.3084
15	20	Biased	4.7727	4.2368	-0.5359
16	20	Unbiased	4.9016	4.2309	-0.6707
17	20	Biased	4.9726	4.31	-0.6626
18	20	Unbiased	4.7119	4.3267	-0.3852
19	20	Biased	4.7257	4.4267	-0.299
20	50	Unbiased	4.9167	4.3514	-0.5653
21	0	Correlation	4.9561	4.3486	-0.6075
22	50	Unbiased	4.7238	4.4261	-0.2977
23	0	Correlation	4.7159	4.2856	-0.4303
24	20	Biased	4.9264	4.3492	-0.5772
26	50	Biased	4.7837	4.4269	-0.3568
27	30	Unbiased	4.7419	4.4079	-0.334
28	30	Biased	4.9236	4.5354	-0.3882
29	30	Unbiased	4.9591	4.4914	-0.4677
30	20	Biased	4.7809	4.2499	-0.531
31	30	Unbiased	4.7427	4.3321	-0.4106
33	30	Biased	4.9791	4.3208	-0.6583
34	50	Unbiased	4.6714	4.3678	-0.3036
35	20	Unbiased	4.6509	4.109	-0.5419
41	30	Biased	4.8586	4.3314	-0.5272

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.7159	4.8931	4.9894	0.12242	4.219	4.3688	4.622	0.1769	-0.7704	-0.52428	-0.2889	0.20955
20	4.6509	4.8064	4.9726	0.11648	4.109	4.3409	4.5989	0.15391	-0.6707	-0.46548	-0.1179	0.17669
30	4.6714	4.8439	4.9791	0.10714	4.3208	4.418	4.6025	0.094851	-0.6583	-0.42589	-0.2715	0.12434
50	4.6262	4.7905	5.0301	0.12692	4.302	4.4241	4.5885	0.078023	-0.6225	-0.36643	-0.161	0.13769

Device Test: 24.28 TIMING|OUT_FALL/OUTH/5.5/12/0/220/5.5/500kHz//@OUT_FALL_220PF





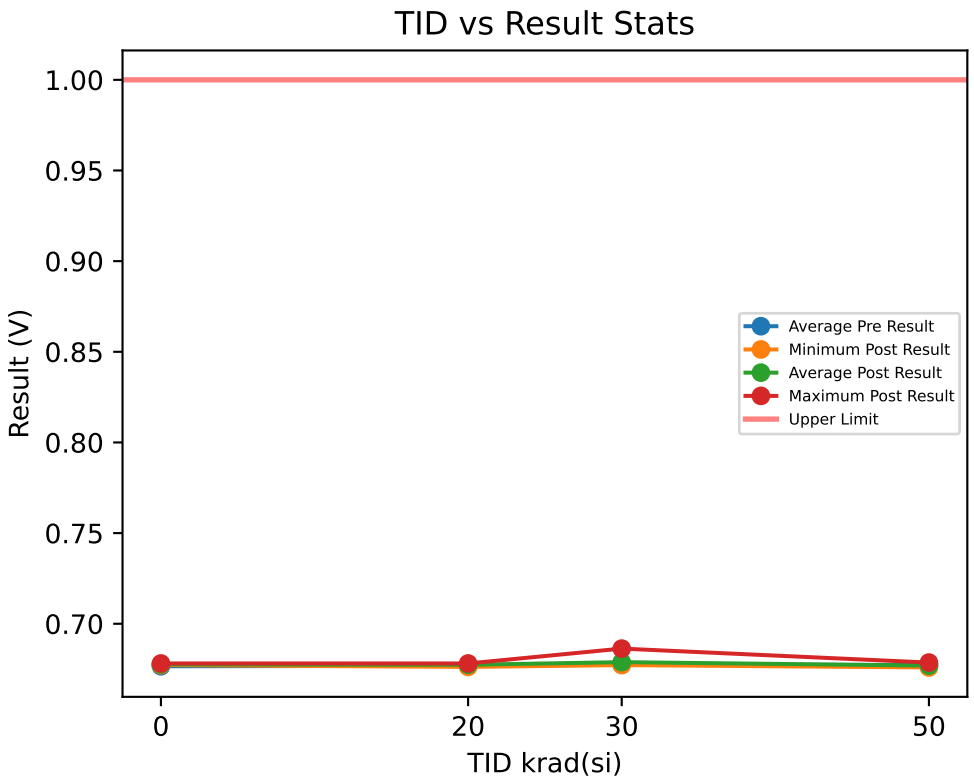
Test Results (Upper Limit = 10.0 (ns))

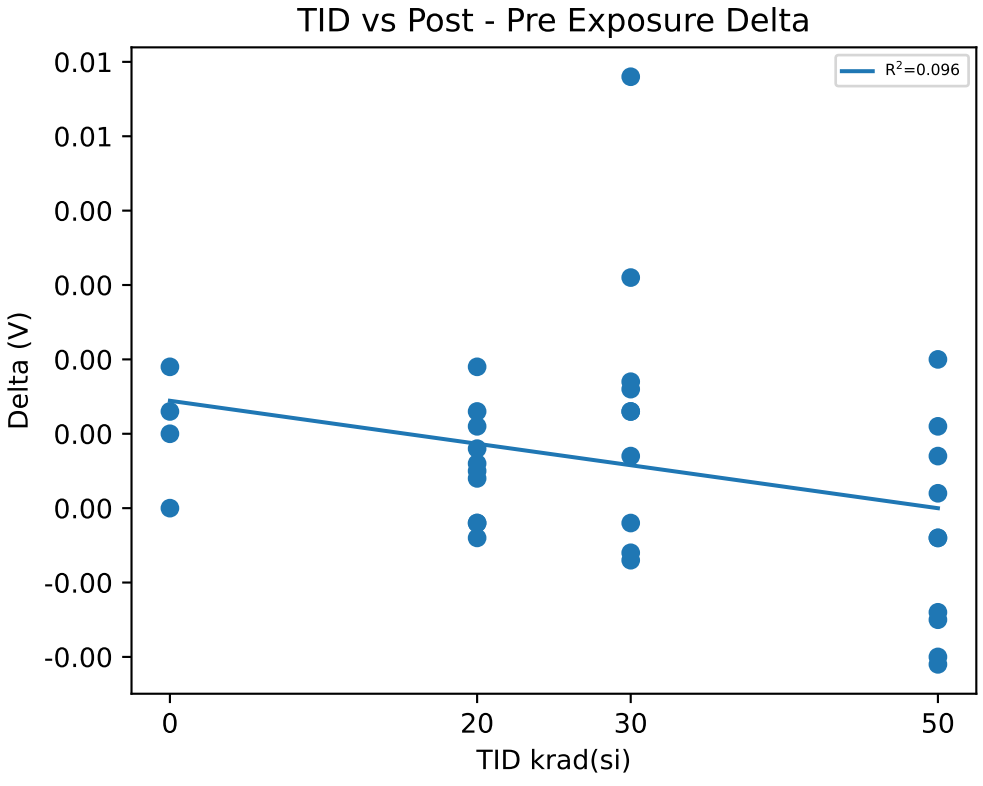
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	4.3888	3.8409	-0.5479
2	20	Unbiased	4.2213	3.8335	-0.3878
3	50	Biased	4.1057	3.8018	-0.3039
4	30	Unbiased	4.1974	3.9166	-0.2808
5	50	Unbiased	4.3925	3.424	-0.9685
6	30	Biased	4.2156	3.462	-0.7536
7	50	Biased	3.9522	3.7595	-0.1927
8	30	Unbiased	4.153	3.7892	-0.3638
9	20	Unbiased	4.3986	3.8696	-0.529
10	50	Biased	4.2033	3.4777	-0.7256
11	30	Biased	4.0171	3.4336	-0.5835
12	0	Correlation	4.0771	3.4407	-0.6364
13	0	Correlation	4.3852	3.8235	-0.5617
14	50	Unbiased	4.2194	3.8433	-0.3761
15	20	Biased	3.9726	3.3963	-0.5763
16	20	Unbiased	4.1671	3.8273	-0.3398
17	20	Biased	4.3509	3.7595	-0.5914
18	20	Unbiased	4.1943	3.767	-0.4273
19	20	Biased	4.0962	3.8143	-0.2819
20	50	Unbiased	4.0854	3.8127	-0.2727
21	0	Correlation	4.4216	3.8557	-0.5659
22	50	Unbiased	4.2395	3.881	-0.3585
23	0	Correlation	4.0002	3.8102	-0.19
24	20	Biased	4.099	3.813	-0.286
26	50	Biased	4.1888	3.7678	-0.421
27	30	Unbiased	4.0055	3.7888	-0.2167
28	30	Biased	4.1106	3.7413	-0.3693
29	30	Unbiased	4.3943	3.8148	-0.5795
30	20	Biased	4.1915	3.4657	-0.7258
31	30	Unbiased	3.9762	3.8496	-0.1266
33	30	Biased	4.3864	3.4551	-0.9313
34	50	Unbiased	4.2799	3.8672	-0.4127
35	20	Unbiased	4.0967	3.4867	-0.61
41	30	Biased	4.1621	3.5366	-0.6255

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.0002	4.221	4.4216	0.21343	3.4407	3.7325	3.8557	0.19549	-0.6364	-0.4885	-0.19	0.20193
20	3.9726	4.1788	4.3986	0.12593	3.3963	3.7033	3.8696	0.17925	-0.7258	-0.47553	-0.2819	0.15239
30	3.9762	4.1618	4.3943	0.14575	3.4336	3.6788	3.9166	0.18553	-0.9313	-0.48306	-0.1266	0.25383
50	3.9522	4.2055	4.3925	0.13511	3.424	3.7476	3.881	0.16168	-0.9685	-0.45796	-0.1927	0.23305

Device Test: 24.29 VOLTAGE|OUT_CLAMP/OUTL/0/0/0/0/0/0//@OUT_CLAMP_0V





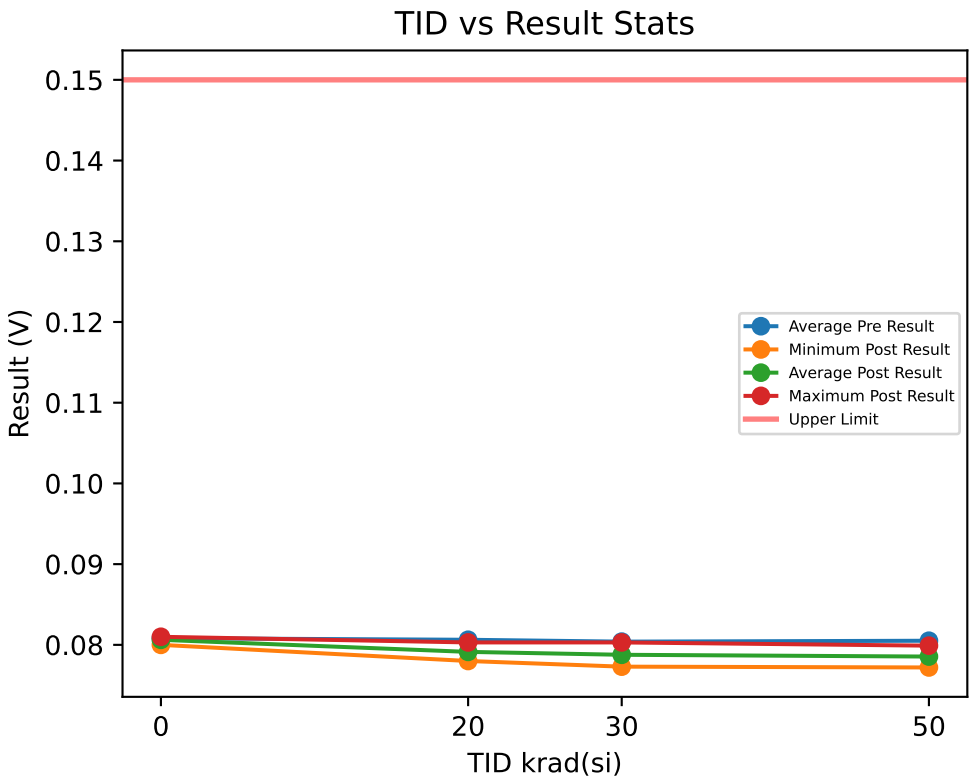
Test Results (Upper Limit = 1.0 (V))

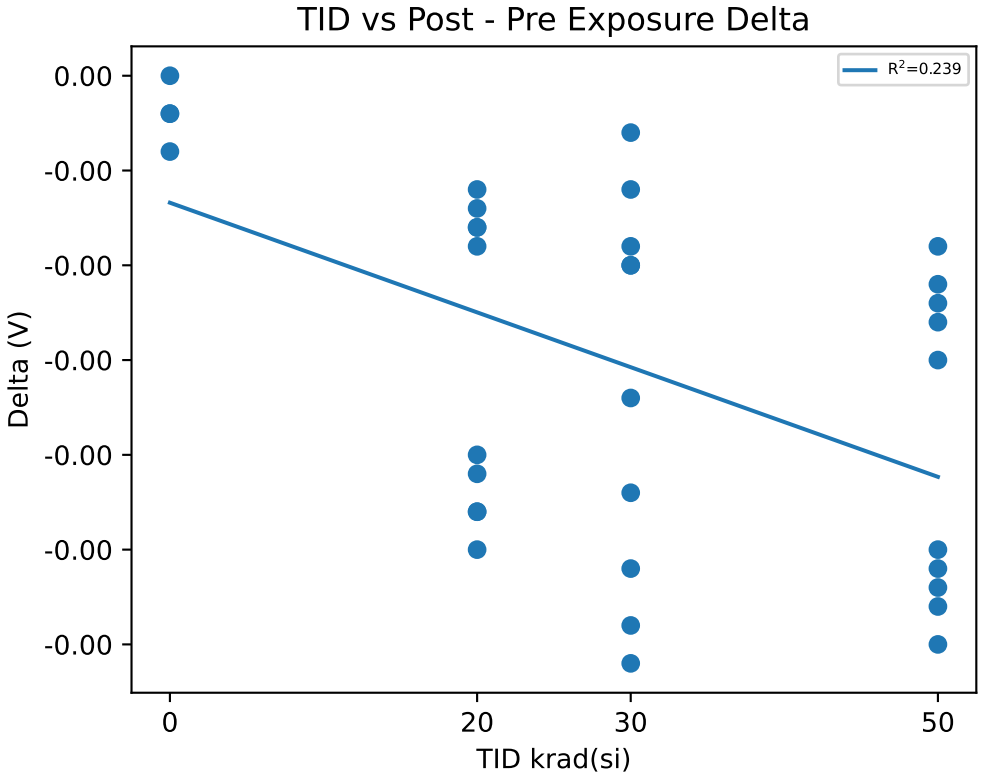
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	0.6793	0.6772	-0.0021
2	20	Unbiased	0.678	0.6778	-0.0002
3	50	Biased	0.6779	0.6759	-0.002
4	30	Unbiased	0.6778	0.6772	-0.0006
5	50	Unbiased	0.6776	0.6762	-0.0014
6	30	Biased	0.6782	0.6775	-0.0007
7	50	Biased	0.6784	0.6769	-0.0015
8	30	Unbiased	0.6789	0.6787	-0.0002
9	20	Unbiased	0.6774	0.6778	0.0004
10	50	Biased	0.6775	0.6771	-0.0004
11	30	Biased	0.6773	0.678	0.0007
12	0	Correlation	0.6781	0.6781	0
13	0	Correlation	0.6767	0.6777	0.001
14	50	Unbiased	0.6766	0.6777	0.0011
15	20	Biased	0.6768	0.6781	0.0013
16	20	Unbiased	0.6775	0.6771	-0.0004
17	20	Biased	0.6764	0.6762	-0.0002
18	20	Unbiased	0.6768	0.6779	0.0011
19	20	Biased	0.6767	0.6772	0.0005
20	50	Unbiased	0.6769	0.6765	-0.0004
21	0	Correlation	0.6759	0.6772	0.0013
22	50	Unbiased	0.6766	0.6786	0.002
23	0	Correlation	0.6755	0.6774	0.0019
24	20	Biased	0.6765	0.6771	0.0006
26	50	Biased	0.676	0.6762	0.0002
27	30	Unbiased	0.6761	0.6774	0.0013
28	30	Biased	0.6768	0.6785	0.0017
29	30	Unbiased	0.6762	0.6775	0.0013
30	20	Biased	0.6758	0.6777	0.0019
31	30	Unbiased	0.6757	0.6788	0.0031
33	30	Biased	0.6768	0.6784	0.0016
34	50	Unbiased	0.6761	0.6768	0.0007
35	20	Unbiased	0.6761	0.6769	0.0008
41	30	Biased	0.6805	0.6863	0.0058

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.6755	0.67655	0.6781	0.0011475	0.6772	0.6776	0.6781	0.00039158	0	0.00105	0.0019	0.00079373
20	0.6758	0.6768	0.678	0.00066999	0.6762	0.67738	0.6781	0.00058271	-0.0004	0.00058	0.0019	0.00072999
30	0.6757	0.67743	0.6805	0.0014682	0.6772	0.67883	0.6863	0.0026883	-0.0007	0.0014	0.0058	0.0019396
50	0.676	0.67729	0.6793	0.0010525	0.6759	0.67691	0.6786	0.0008034	-0.0021	-0.00038	0.002	0.0013839

Device Test: 24.3 LEVEL|LOW_LEVEL/OUTL/5/5/0/0/5/500kHz//@OUT_VOL





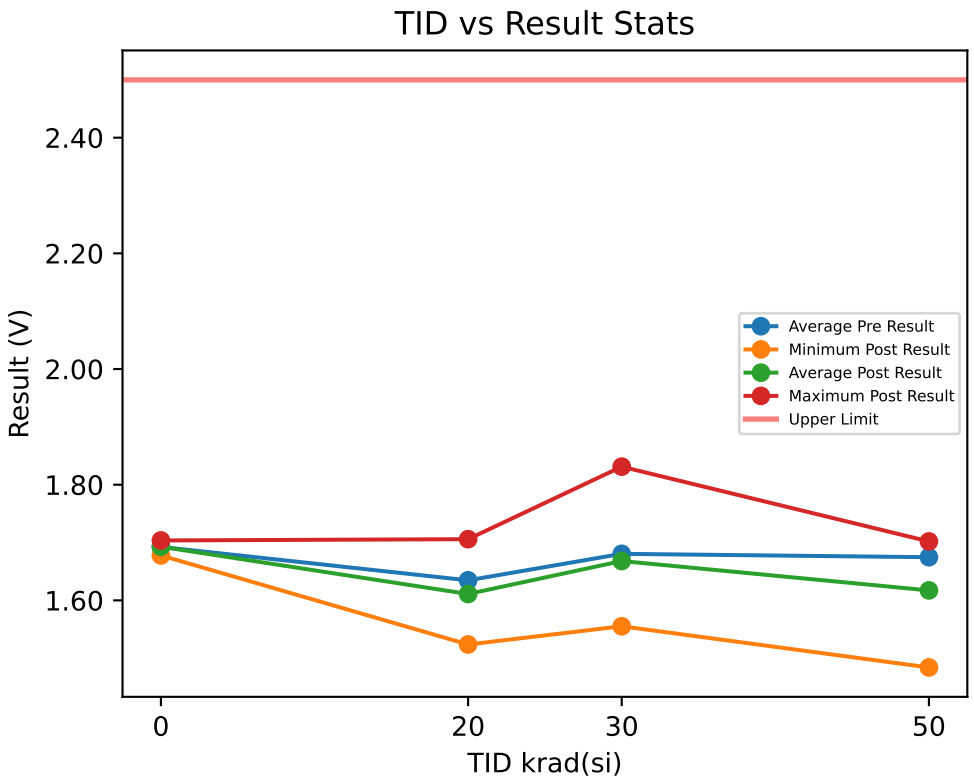
Test Results (Upper Limit = 0.15 (V))

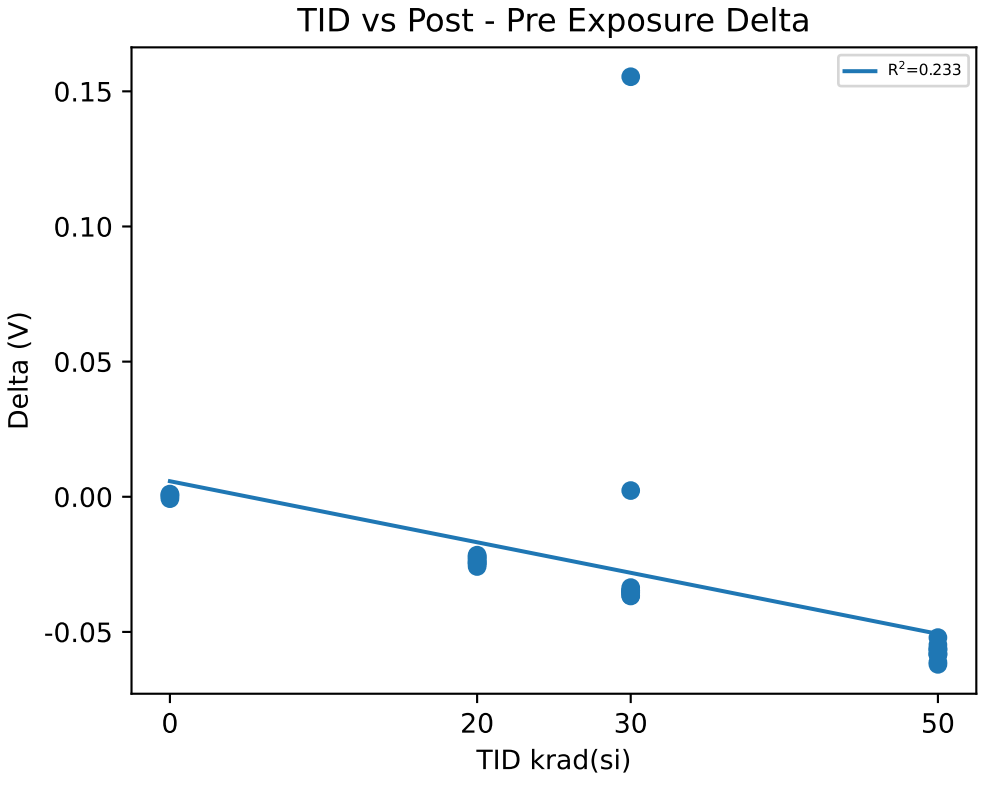
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	0.0799	0.0772	-0.0027
2	20	Unbiased	0.08	0.0794	-0.0006
3	50	Biased	0.0801	0.0776	-0.0025
4	30	Unbiased	0.08	0.0791	-0.0009
5	50	Unbiased	0.0804	0.0795	-0.0009
6	30	Biased	0.0806	0.0784	-0.0022
7	50	Biased	0.0807	0.0781	-0.0026
8	30	Unbiased	0.0799	0.0793	-0.0006
9	20	Unbiased	0.0804	0.0797	-0.0007
10	50	Biased	0.0808	0.078	-0.0028
11	30	Biased	0.0799	0.0773	-0.0026
12	0	Correlation	0.0807	0.0807	0
13	0	Correlation	0.0812	0.081	-0.0002
14	50	Unbiased	0.0806	0.0794	-0.0012
15	20	Biased	0.0806	0.0783	-0.0023
16	20	Unbiased	0.0809	0.0801	-0.0008
17	20	Biased	0.0811	0.0791	-0.002
18	20	Unbiased	0.0812	0.0803	-0.0009
19	20	Biased	0.0803	0.078	-0.0023
20	50	Unbiased	0.081	0.0799	-0.0011
21	0	Correlation	0.0802	0.08	-0.0002
22	50	Unbiased	0.0806	0.0791	-0.0015
23	0	Correlation	0.0812	0.0808	-0.0004
24	20	Biased	0.081	0.0789	-0.0021
26	50	Biased	0.0808	0.0778	-0.003
27	30	Unbiased	0.0808	0.0798	-0.001
28	30	Biased	0.0808	0.0779	-0.0029
29	30	Unbiased	0.0799	0.0789	-0.001
30	20	Biased	0.0808	0.0783	-0.0025
31	30	Unbiased	0.0806	0.0803	-0.0003
33	30	Biased	0.0816	0.0785	-0.0031
34	50	Unbiased	0.0802	0.0789	-0.0013
35	20	Unbiased	0.08	0.0792	-0.0008
41	30	Biased	0.0799	0.0782	-0.0017

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.0802	0.080825	0.0812	0.00047871	0.08	0.080625	0.081	0.00043493	-0.0004	-0.0002	0	0.0001633
20	0.08	0.08063	0.0812	0.00043982	0.078	0.07913	0.0803	0.0007761	-0.0025	-0.0015	-0.0006	0.00079443
30	0.0799	0.0804	0.0816	0.00057735	0.0773	0.07877	0.0803	0.00089821	-0.0031	-0.00163	-0.0003	0.0010111
50	0.0799	0.08051	0.081	0.00035103	0.0772	0.07855	0.0799	0.00092286	-0.003	-0.00196	-0.0009	0.00082489

Device Test: 24.30 VOLTAGE|OUT_CLAMP/OUTL/5/0/0/0/0/0//@OUT_CLAMP_FULL





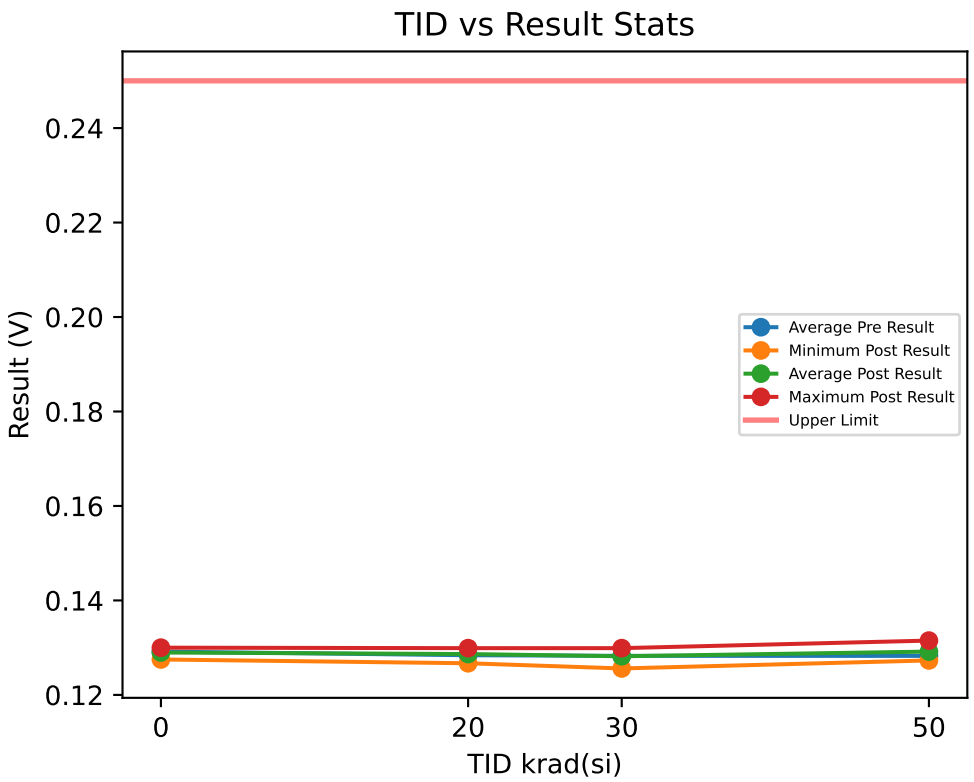
Test Results (Upper Limit = 2.5 (V))

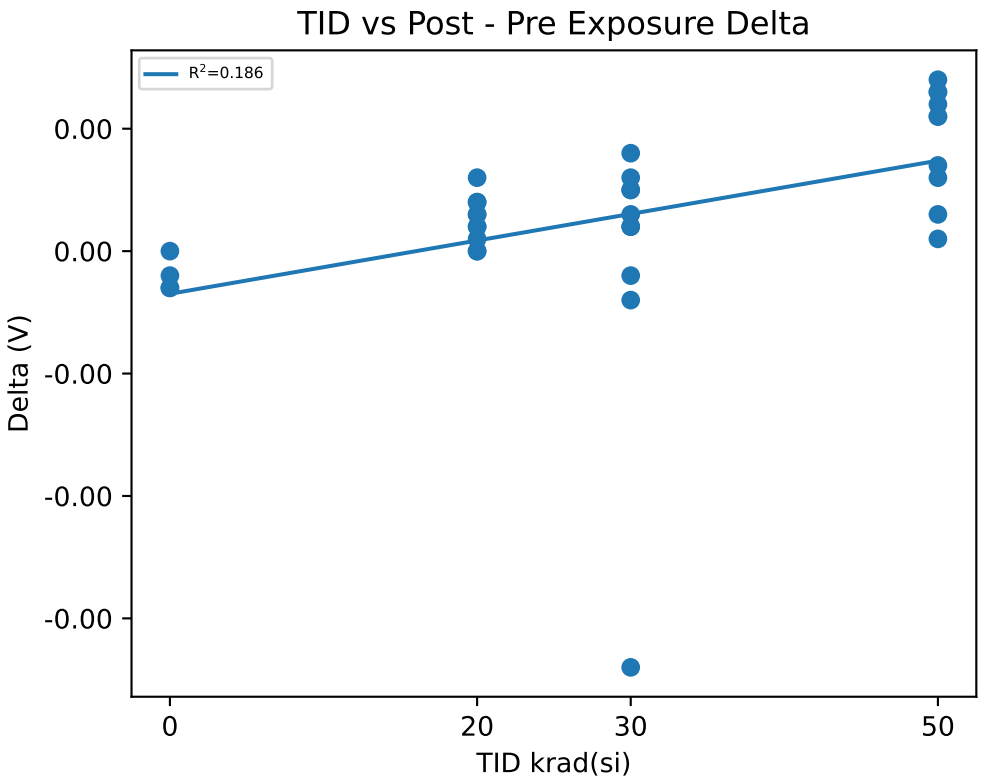
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	1.6366	1.5785	-0.0581
2	20	Unbiased	1.5461	1.5237	-0.0224
3	50	Biased	1.5402	1.484	-0.0562
4	30	Unbiased	1.6101	1.5734	-0.0367
5	50	Unbiased	1.6541	1.5921	-0.062
6	30	Biased	1.7406	1.7041	-0.0365
7	50	Biased	1.6744	1.6196	-0.0548
8	30	Unbiased	1.6641	1.6295	-0.0346
9	20	Unbiased	1.6812	1.6567	-0.0245
10	50	Biased	1.7596	1.7015	-0.0581
11	30	Biased	1.5888	1.5552	-0.0336
12	0	Correlation	1.7043	1.7036	-0.0007
13	0	Correlation	1.6953	1.6954	0.0001
14	50	Unbiased	1.754	1.7019	-0.0521
15	20	Biased	1.6161	1.5931	-0.023
16	20	Unbiased	1.7243	1.6985	-0.0258
17	20	Biased	1.6247	1.5996	-0.0251
18	20	Unbiased	1.5721	1.5487	-0.0234
19	20	Biased	1.6452	1.6209	-0.0243
20	50	Unbiased	1.666	1.6048	-0.0612
21	0	Correlation	1.677	1.6777	0.0007
22	50	Unbiased	1.7348	1.6785	-0.0563
23	0	Correlation	1.6932	1.6942	0.001
24	20	Biased	1.6437	1.6221	-0.0216
26	50	Biased	1.6583	1.6015	-0.0568
27	30	Unbiased	1.7046	1.669	-0.0356
28	30	Biased	1.7396	1.7042	-0.0354
29	30	Unbiased	1.6237	1.589	-0.0347
30	20	Biased	1.7278	1.7058	-0.022
31	30	Unbiased	1.6542	1.6565	0.0023
33	30	Biased	1.8029	1.7679	-0.035
34	50	Unbiased	1.6684	1.6099	-0.0585
35	20	Unbiased	1.5652	1.541	-0.0242
41	30	Biased	1.6758	1.8312	0.1554

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.677	1.6925	1.7043	0.01137	1.6777	1.6927	1.7036	0.010853	-0.0007	0.000275	0.001	0.00075
20	1.5461	1.6346	1.7278	0.063328	1.5237	1.611	1.7058	0.063075	-0.0258	-0.02363	-0.0216	0.0013801
30	1.5888	1.6804	1.8029	0.066868	1.5552	1.668	1.8312	0.087405	-0.0367	-0.01244	0.1554	0.06015
50	1.5402	1.6746	1.7596	0.064515	1.484	1.6172	1.7019	0.065292	-0.062	-0.05741	-0.0521	0.0028992

Device Test: 24.4 LEVEL|HIGH_LEVEL/OUTH/5/5/0/0/5/500kHz//@OUT_VOH





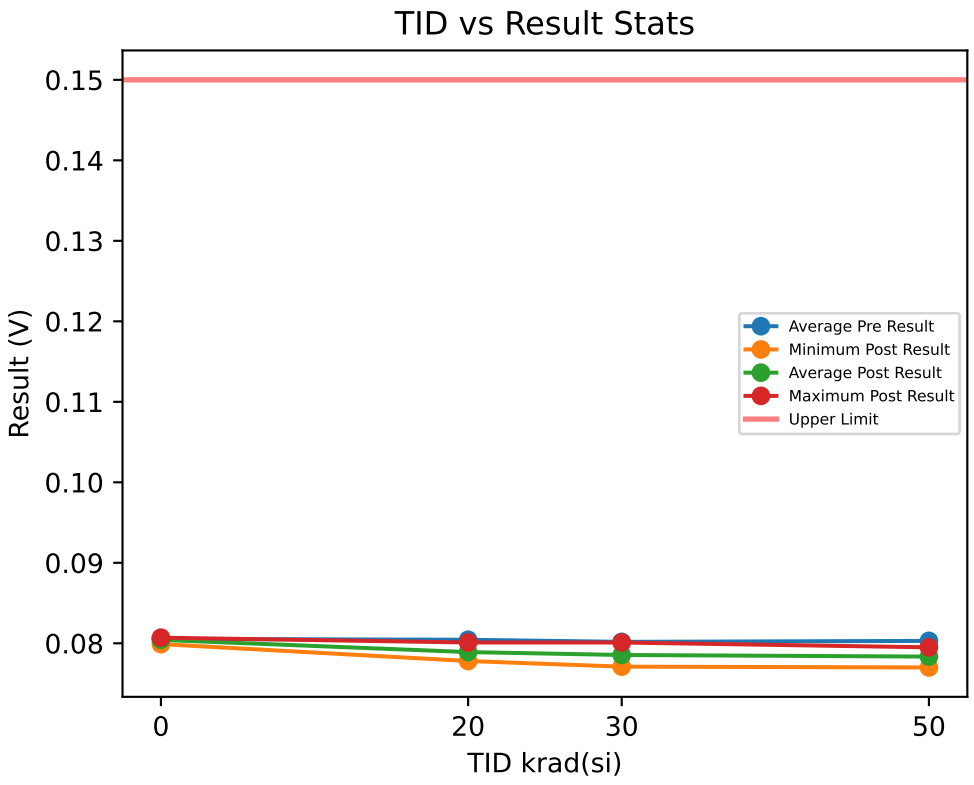
Test Results (Upper Limit = 0.25 (V))

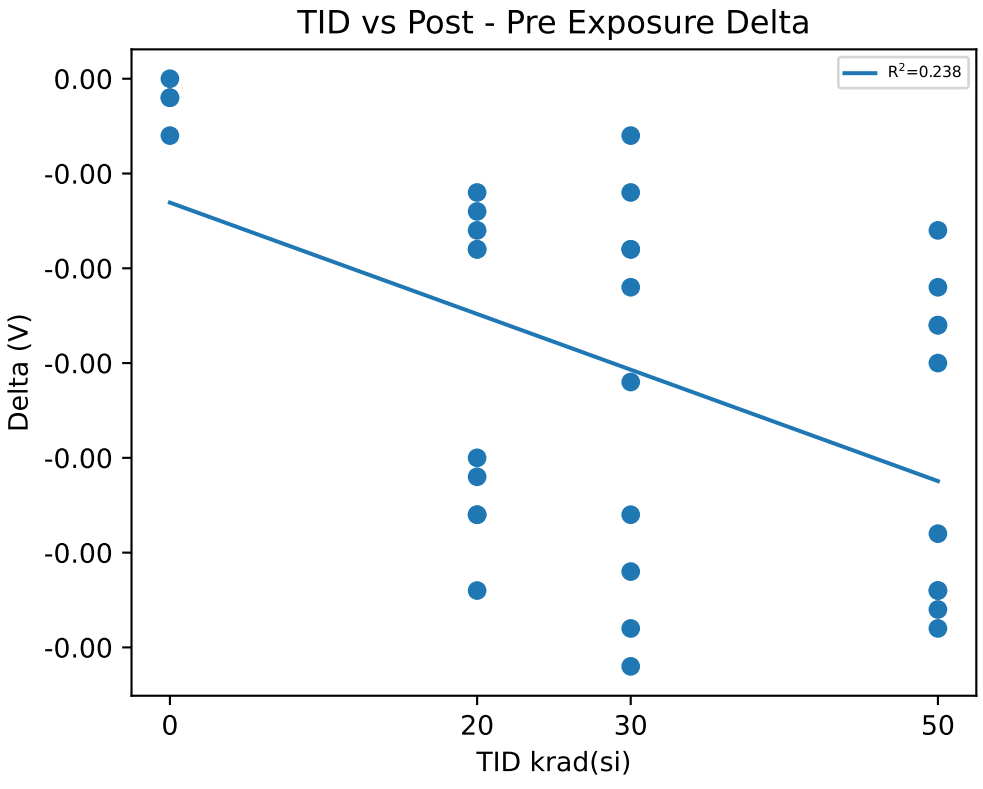
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	0.1262	0.1276	0.0014
2	20	Unbiased	0.1266	0.127	0.0004
3	50	Biased	0.1266	0.1279	0.0013
4	30	Unbiased	0.1262	0.1267	0.0005
5	50	Unbiased	0.1296	0.1308	0.0012
6	30	Biased	0.1293	0.1299	0.0006
7	50	Biased	0.1299	0.1312	0.0013
8	30	Unbiased	0.1264	0.1272	0.0008
9	20	Unbiased	0.1273	0.1275	0.0002
10	50	Biased	0.127	0.1281	0.0011
11	30	Biased	0.127	0.1275	0.0005
12	0	Correlation	0.13	0.13	0
13	0	Correlation	0.1296	0.1293	-0.0003
14	50	Unbiased	0.1281	0.1284	0.0003
15	20	Biased	0.1298	0.1298	0
16	20	Unbiased	0.129	0.1294	0.0004
17	20	Biased	0.1292	0.1298	0.0006
18	20	Unbiased	0.1297	0.1299	0.0002
19	20	Biased	0.1269	0.1272	0.0003
20	50	Unbiased	0.1309	0.1315	0.0006
21	0	Correlation	0.1277	0.1275	-0.0002
22	50	Unbiased	0.1281	0.1282	0.0001
23	0	Correlation	0.1294	0.1291	-0.0003
24	20	Biased	0.1295	0.1298	0.0003
26	50	Biased	0.1296	0.1307	0.0011
27	30	Unbiased	0.1297	0.1295	-0.0002
28	30	Biased	0.1296	0.1298	0.0002
29	30	Unbiased	0.1269	0.1271	0.0002
30	20	Biased	0.1293	0.1294	0.0001
31	30	Unbiased	0.1294	0.129	-0.0004
33	30	Biased	0.1292	0.1295	0.0003
34	50	Unbiased	0.1266	0.1273	0.0007
35	20	Unbiased	0.1267	0.1267	0
41	30	Biased	0.129	0.1256	-0.0034

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.1277	0.12917	0.13	0.0010145	0.1275	0.12898	0.13	0.0010563	-0.0003	-0.0002	0	0.00014142
20	0.1266	0.1284	0.1298	0.0013441	0.1267	0.12865	0.1299	0.0013583	0	0.00025	0.0006	0.00019003
30	0.1262	0.12827	0.1297	0.0014461	0.1256	0.12818	0.1299	0.0015339	-0.0034	-9e-05	0.0008	0.0012179
50	0.1262	0.12826	0.1309	0.0016548	0.1273	0.12917	0.1315	0.00166	0.0001	0.00091	0.0014	0.0004557

Device Test: 24.5 LEVEL|LOW_LEVEL/OUTL/12/12/0/0/5/500kHz//@OUT_VOL





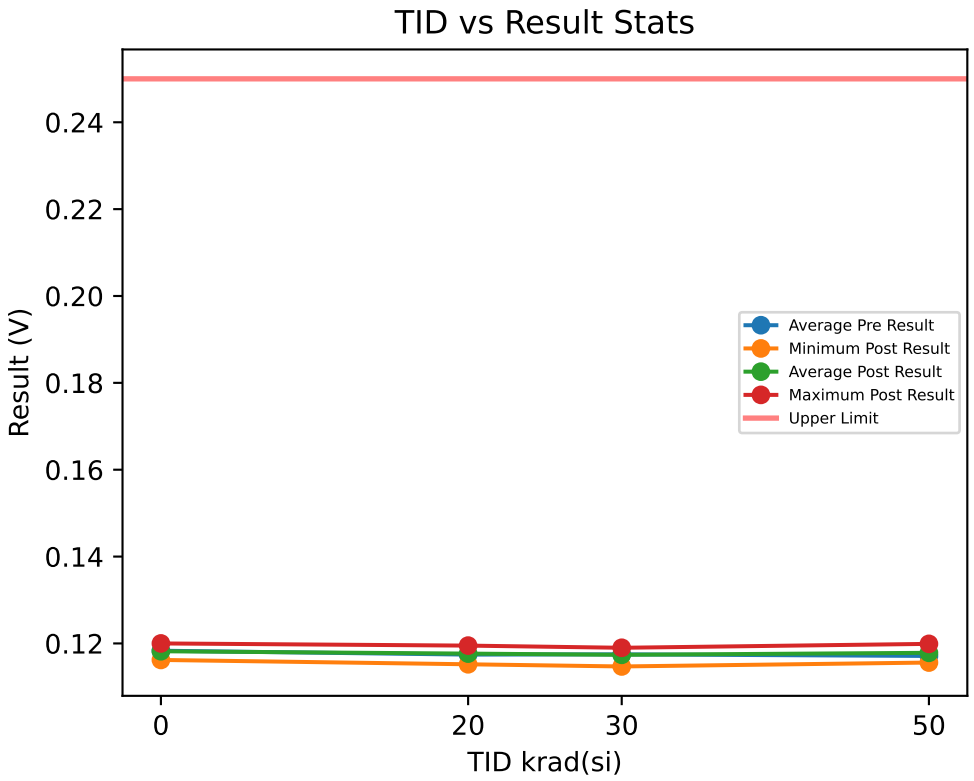
Test Results (Upper Limit = 0.15 (V))

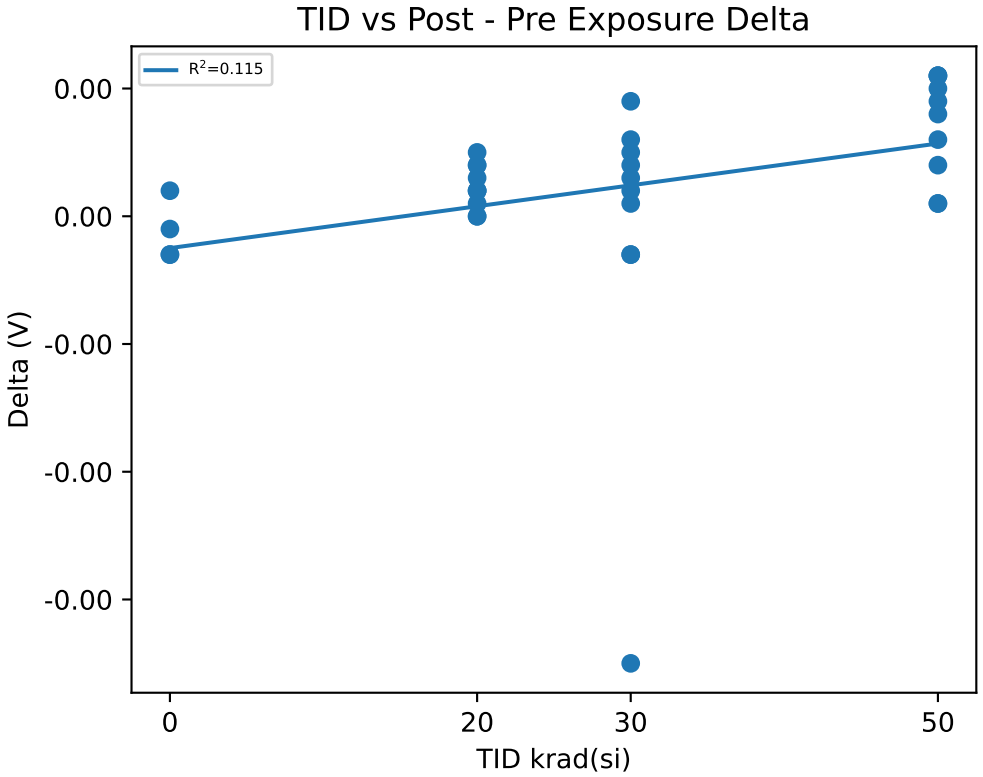
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	0.0797	0.077	-0.0027
2	20	Unbiased	0.0798	0.0792	-0.0006
3	50	Biased	0.0798	0.0774	-0.0024
4	30	Unbiased	0.0798	0.0789	-0.0009
5	50	Unbiased	0.0802	0.0794	-0.0008
6	30	Biased	0.0805	0.0782	-0.0023
7	50	Biased	0.0805	0.0778	-0.0027
8	30	Unbiased	0.0797	0.0791	-0.0006
9	20	Unbiased	0.0803	0.0796	-0.0007
10	50	Biased	0.0807	0.0779	-0.0028
11	30	Biased	0.0797	0.0771	-0.0026
12	0	Correlation	0.0805	0.0805	0
13	0	Correlation	0.0808	0.0807	-0.0001
14	50	Unbiased	0.0805	0.0792	-0.0013
15	20	Biased	0.0804	0.0781	-0.0023
16	20	Unbiased	0.0807	0.0799	-0.0008
17	20	Biased	0.0809	0.0789	-0.002
18	20	Unbiased	0.081	0.0801	-0.0009
19	20	Biased	0.0801	0.0778	-0.0023
20	50	Unbiased	0.0806	0.0795	-0.0011
21	0	Correlation	0.08	0.0799	-0.0001
22	50	Unbiased	0.0804	0.0789	-0.0015
23	0	Correlation	0.0809	0.0806	-0.0003
24	20	Biased	0.0807	0.0786	-0.0021
26	50	Biased	0.0806	0.0777	-0.0029
27	30	Unbiased	0.0805	0.0796	-0.0009
28	30	Biased	0.0805	0.0776	-0.0029
29	30	Unbiased	0.0797	0.0786	-0.0011
30	20	Biased	0.0807	0.078	-0.0027
31	30	Unbiased	0.0804	0.0801	-0.0003
33	30	Biased	0.0813	0.0782	-0.0031
34	50	Unbiased	0.08	0.0787	-0.0013
35	20	Unbiased	0.0798	0.0789	-0.0009
41	30	Biased	0.0797	0.0781	-0.0016

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.08	0.08055	0.0809	0.00040415	0.0799	0.080425	0.0807	0.0003594	-0.0003	-0.000125	0	0.00012583
20	0.0798	0.08044	0.081	0.00043256	0.0778	0.07891	0.0801	0.00080062	-0.0027	-0.00153	-0.0006	0.0008152
30	0.0797	0.08018	0.0813	0.00054528	0.0771	0.07855	0.0801	0.00090585	-0.0031	-0.00163	-0.0003	0.0010188
50	0.0797	0.0803	0.0807	0.0003559	0.077	0.07835	0.0795	0.00089598	-0.0029	-0.00195	-0.0008	0.00081955

Device Test: 24.6 LEVEL|HIGH_LEVEL/OUTH/12/12/0/0/5/500kHz//@OUT_VOH





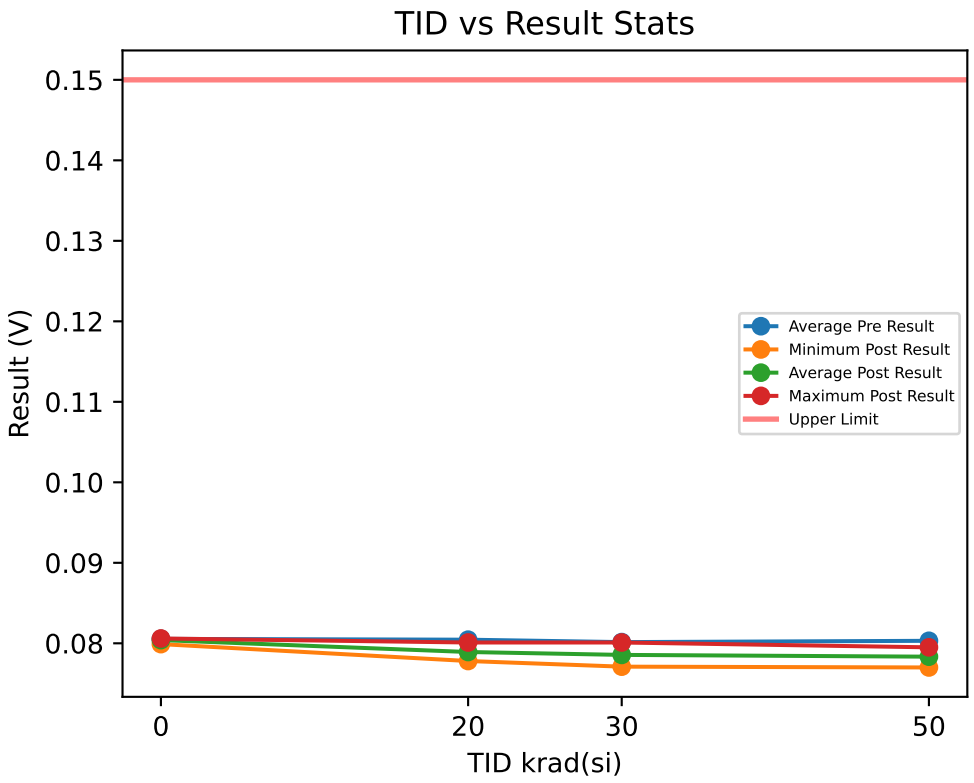
Test Results (Upper Limit = 0.25 (V))

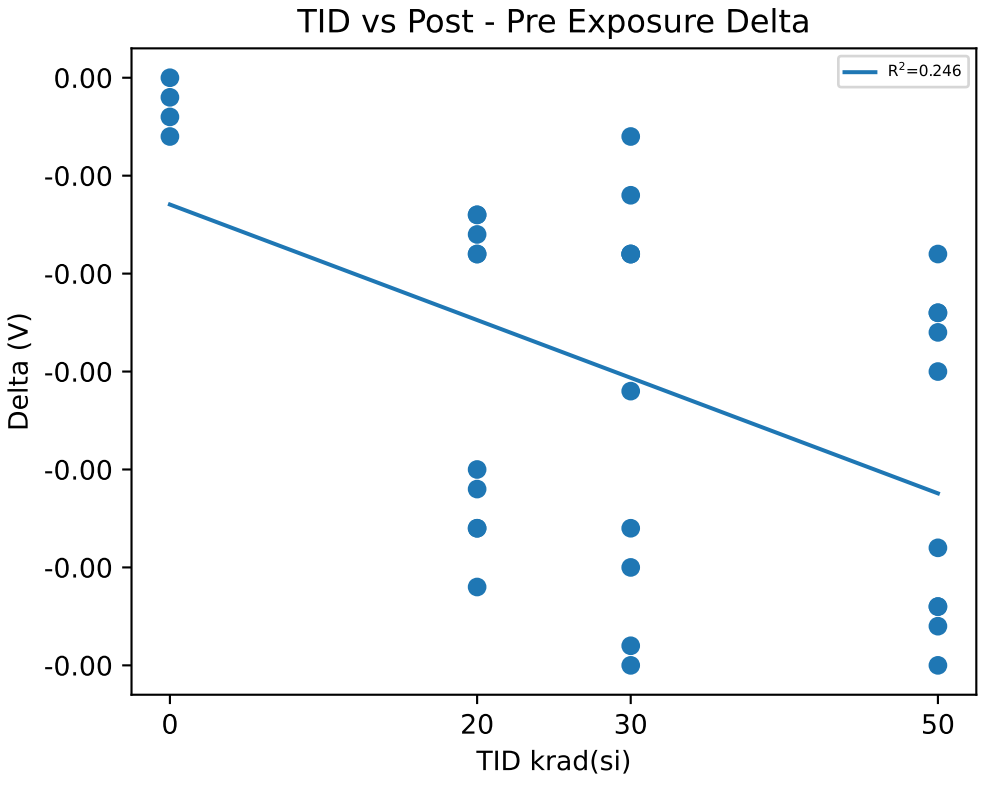
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	0.1153	0.1164	0.0011
2	20	Unbiased	0.1155	0.116	0.0005
3	50	Biased	0.1161	0.1172	0.0011
4	30	Unbiased	0.1154	0.1158	0.0004
5	50	Unbiased	0.1184	0.1192	0.0008
6	30	Biased	0.1181	0.1186	0.0005
7	50	Biased	0.1185	0.1194	0.0009
8	30	Unbiased	0.1152	0.1161	0.0009
9	20	Unbiased	0.1171	0.1173	0.0002
10	50	Biased	0.1166	0.1177	0.0011
11	30	Biased	0.1168	0.1174	0.0006
12	0	Correlation	0.1198	0.12	0.0002
13	0	Correlation	0.1188	0.1185	-0.0003
14	50	Unbiased	0.1172	0.1173	0.0001
15	20	Biased	0.1195	0.1195	0
16	20	Unbiased	0.1175	0.1179	0.0004
17	20	Biased	0.1187	0.1191	0.0004
18	20	Unbiased	0.1184	0.1186	0.0002
19	20	Biased	0.1162	0.1165	0.0003
20	50	Unbiased	0.1193	0.1199	0.0006
21	0	Correlation	0.1163	0.1162	-0.0001
22	50	Unbiased	0.1166	0.1167	0.0001
23	0	Correlation	0.1184	0.1181	-0.0003
24	20	Biased	0.1185	0.1187	0.0002
26	50	Biased	0.118	0.119	0.001
27	30	Unbiased	0.119	0.1187	-0.0003
28	30	Biased	0.1184	0.1185	0.0001
29	30	Unbiased	0.1167	0.1169	0.0002
30	20	Biased	0.1177	0.1178	0.0001
31	30	Unbiased	0.1184	0.1181	-0.0003
33	30	Biased	0.1187	0.119	0.0003
34	50	Unbiased	0.1152	0.1156	0.0004
35	20	Unbiased	0.1152	0.1152	0
41	30	Biased	0.1182	0.1147	-0.0035

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.1163	0.11832	0.1198	0.0014728	0.1162	0.1182	0.12	0.0015642	-0.0003	-0.000125	0.0002	0.00023629
20	0.1152	0.11743	0.1195	0.0014291	0.1152	0.11766	0.1195	0.0014057	0	0.00023	0.0005	0.00017029
30	0.1152	0.11749	0.119	0.0013739	0.1147	0.11738	0.119	0.0014597	-0.0035	-0.00011	0.0009	0.0012485
50	0.1152	0.11712	0.1193	0.0014006	0.1156	0.11784	0.1199	0.0014524	0.0001	0.00072	0.0011	0.00039944

Device Test: 24.7 LEVEL|LOW_LEVEL/OUTL/14/14/0/0/5/500kHz//@OUT_VOL





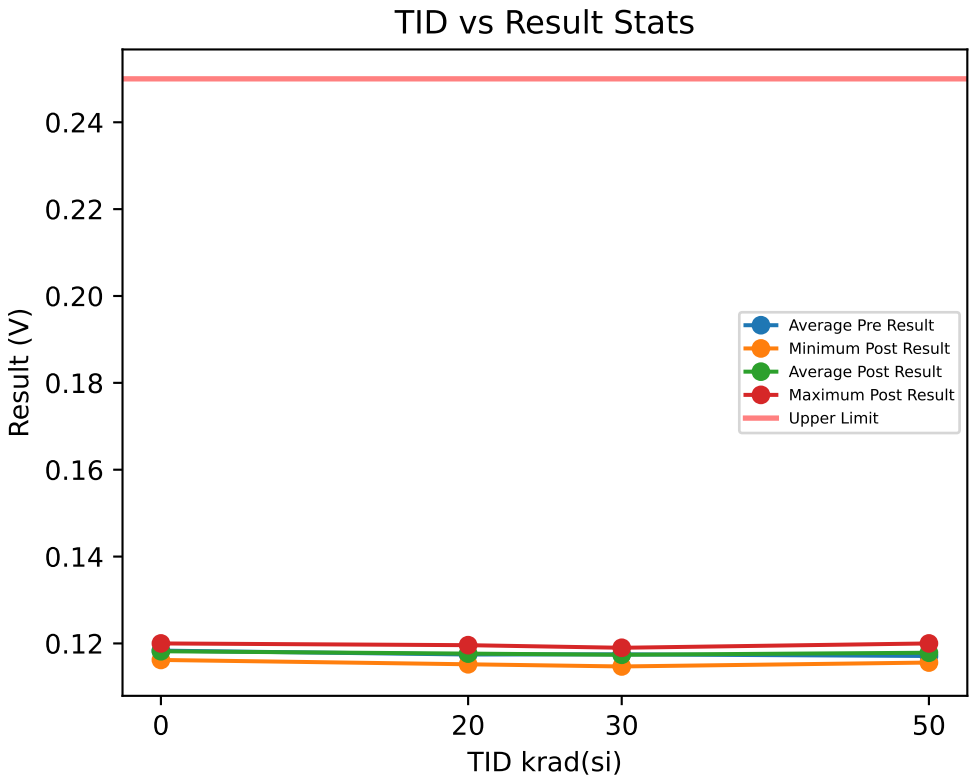
Test Results (Upper Limit = 0.15 (V))

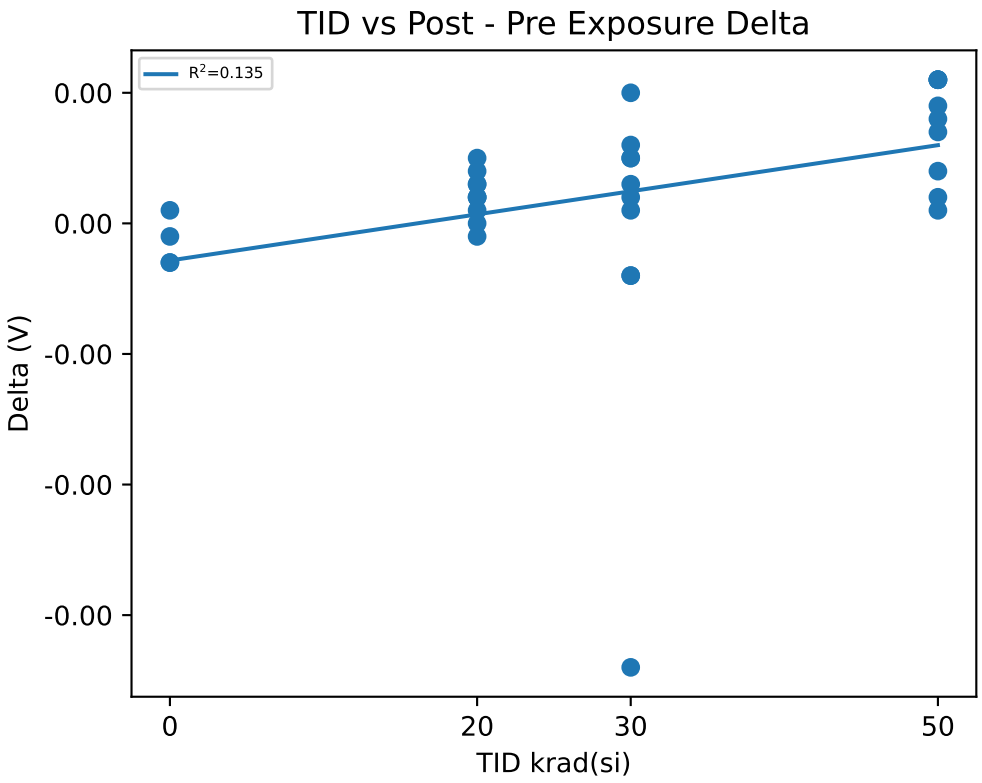
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	0.0797	0.077	-0.0027
2	20	Unbiased	0.0799	0.0792	-0.0007
3	50	Biased	0.0798	0.0774	-0.0024
4	30	Unbiased	0.0798	0.0789	-0.0009
5	50	Unbiased	0.0803	0.0794	-0.0009
6	30	Biased	0.0805	0.0782	-0.0023
7	50	Biased	0.0805	0.0778	-0.0027
8	30	Unbiased	0.0797	0.0791	-0.0006
9	20	Unbiased	0.0803	0.0796	-0.0007
10	50	Biased	0.0807	0.0779	-0.0028
11	30	Biased	0.0796	0.0771	-0.0025
12	0	Correlation	0.0805	0.0805	0
13	0	Correlation	0.0808	0.0806	-0.0002
14	50	Unbiased	0.0804	0.0792	-0.0012
15	20	Biased	0.0804	0.0781	-0.0023
16	20	Unbiased	0.0807	0.0799	-0.0008
17	20	Biased	0.0809	0.0789	-0.002
18	20	Unbiased	0.081	0.0801	-0.0009
19	20	Biased	0.0801	0.0778	-0.0023
20	50	Unbiased	0.0807	0.0795	-0.0012
21	0	Correlation	0.08	0.0799	-0.0001
22	50	Unbiased	0.0804	0.0789	-0.0015
23	0	Correlation	0.0809	0.0806	-0.0003
24	20	Biased	0.0807	0.0786	-0.0021
26	50	Biased	0.0806	0.0776	-0.003
27	30	Unbiased	0.0805	0.0796	-0.0009
28	30	Biased	0.0805	0.0776	-0.0029
29	30	Unbiased	0.0796	0.0787	-0.0009
30	20	Biased	0.0807	0.0781	-0.0026
31	30	Unbiased	0.0804	0.0801	-0.0003
33	30	Biased	0.0812	0.0782	-0.003
34	50	Unbiased	0.08	0.0787	-0.0013
35	20	Unbiased	0.0798	0.0789	-0.0009
41	30	Biased	0.0797	0.0781	-0.0016

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.08	0.08055	0.0809	0.00040415	0.0799	0.0804	0.0806	0.00033665	-0.0003	-0.00015	0	0.0001291
20	0.0798	0.08045	0.081	0.000417	0.0778	0.07892	0.0801	0.00078853	-0.0026	-0.00153	-0.0007	0.00078747
30	0.0796	0.08015	0.0812	0.00054416	0.0771	0.07856	0.0801	0.00090701	-0.003	-0.00159	-0.0003	0.001006
50	0.0797	0.08031	0.0807	0.0003604	0.077	0.07834	0.0795	0.00090456	-0.003	-0.00197	-0.0009	0.00081656

Device Test: 24.8 LEVEL|HIGH_LEVEL/OUTH/14/14/0/0/5/500kHz//@OUT_VOH





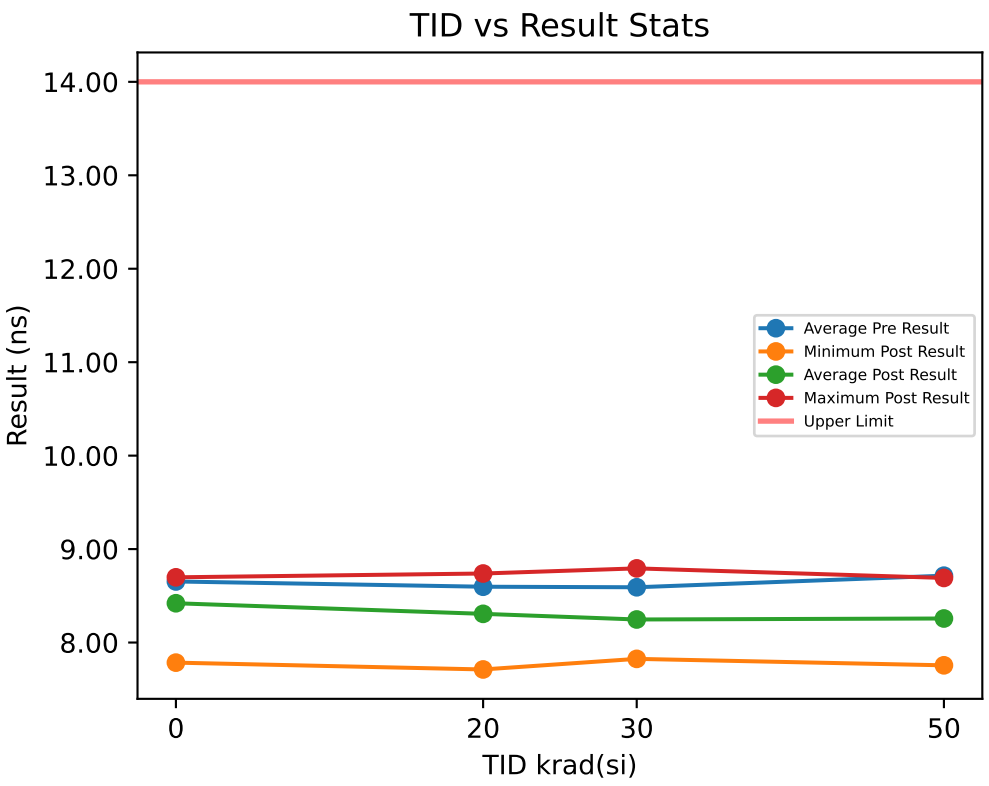
Test Results (Upper Limit = 0.25 (V))

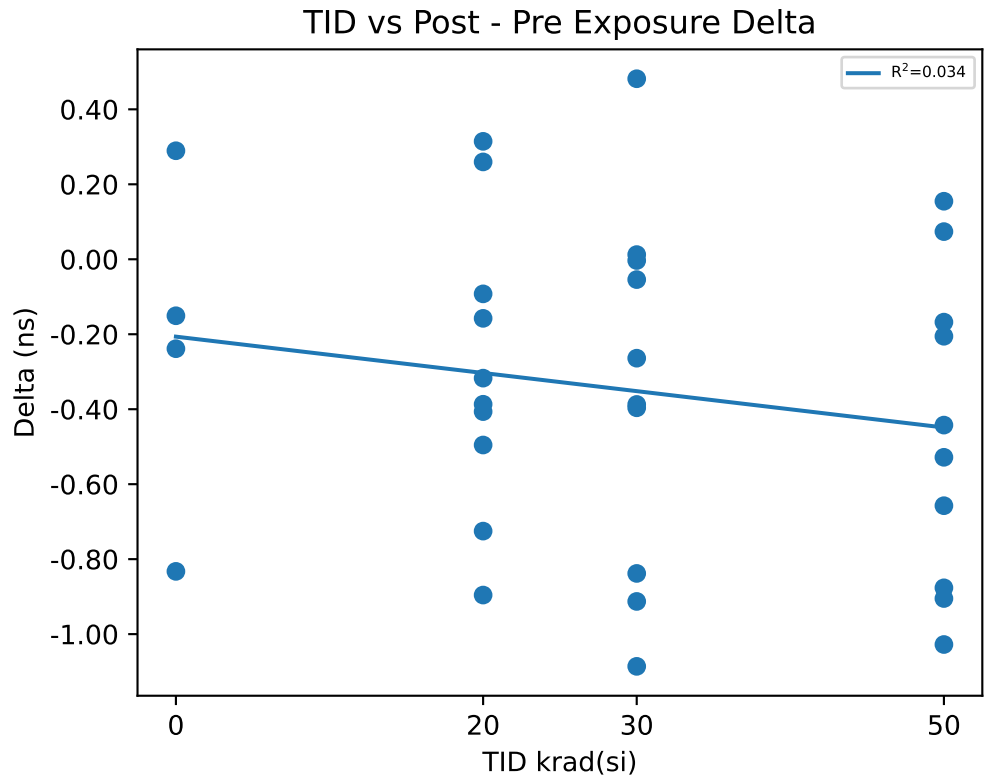
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	0.1153	0.1164	0.0011
2	20	Unbiased	0.1155	0.1159	0.0004
3	50	Biased	0.1161	0.1172	0.0011
4	30	Unbiased	0.1153	0.1158	0.0005
5	50	Unbiased	0.1184	0.1192	0.0008
6	30	Biased	0.118	0.1186	0.0006
7	50	Biased	0.1185	0.1194	0.0009
8	30	Unbiased	0.1152	0.1162	0.001
9	20	Unbiased	0.117	0.1173	0.0003
10	50	Biased	0.1166	0.1177	0.0011
11	30	Biased	0.1169	0.1174	0.0005
12	0	Correlation	0.1199	0.12	0.0001
13	0	Correlation	0.1188	0.1185	-0.0003
14	50	Unbiased	0.1172	0.1173	0.0001
15	20	Biased	0.1196	0.1196	0
16	20	Unbiased	0.1176	0.1179	0.0003
17	20	Biased	0.1186	0.1191	0.0005
18	20	Unbiased	0.1185	0.1187	0.0002
19	20	Biased	0.1162	0.1164	0.0002
20	50	Unbiased	0.1193	0.12	0.0007
21	0	Correlation	0.1163	0.1162	-0.0001
22	50	Unbiased	0.1166	0.1168	0.0002
23	0	Correlation	0.1184	0.1181	-0.0003
24	20	Biased	0.1185	0.1187	0.0002
26	50	Biased	0.1179	0.119	0.0011
27	30	Unbiased	0.1191	0.1187	-0.0004
28	30	Biased	0.1184	0.1185	0.0001
29	30	Unbiased	0.1167	0.1169	0.0002
30	20	Biased	0.1177	0.1178	0.0001
31	30	Unbiased	0.1185	0.1181	-0.0004
33	30	Biased	0.1187	0.119	0.0003
34	50	Unbiased	0.1152	0.1156	0.0004
35	20	Unbiased	0.1153	0.1152	-0.0001
41	30	Biased	0.1181	0.1147	-0.0034

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.1163	0.11835	0.1199	0.0015067	0.1162	0.1182	0.12	0.0015642	-0.0003	-0.00015	0.0001	0.00019149
20	0.1153	0.11745	0.1196	0.0014308	0.1152	0.11766	0.1196	0.0014508	-0.0001	0.00021	0.0005	0.0001792
30	0.1152	0.11749	0.1191	0.0013964	0.1147	0.11739	0.119	0.0014502	-0.0034	-0.0001	0.001	0.0012374
50	0.1152	0.11711	0.1193	0.001394	0.1156	0.11786	0.12	0.00146	0.0001	0.00075	0.0011	0.00038944

Device Test: 24.9 TIMING|OUT_RISE/OUTH/4.5/4.5/0/1000/4.5/500kHz//@OUT_RISE_4P5





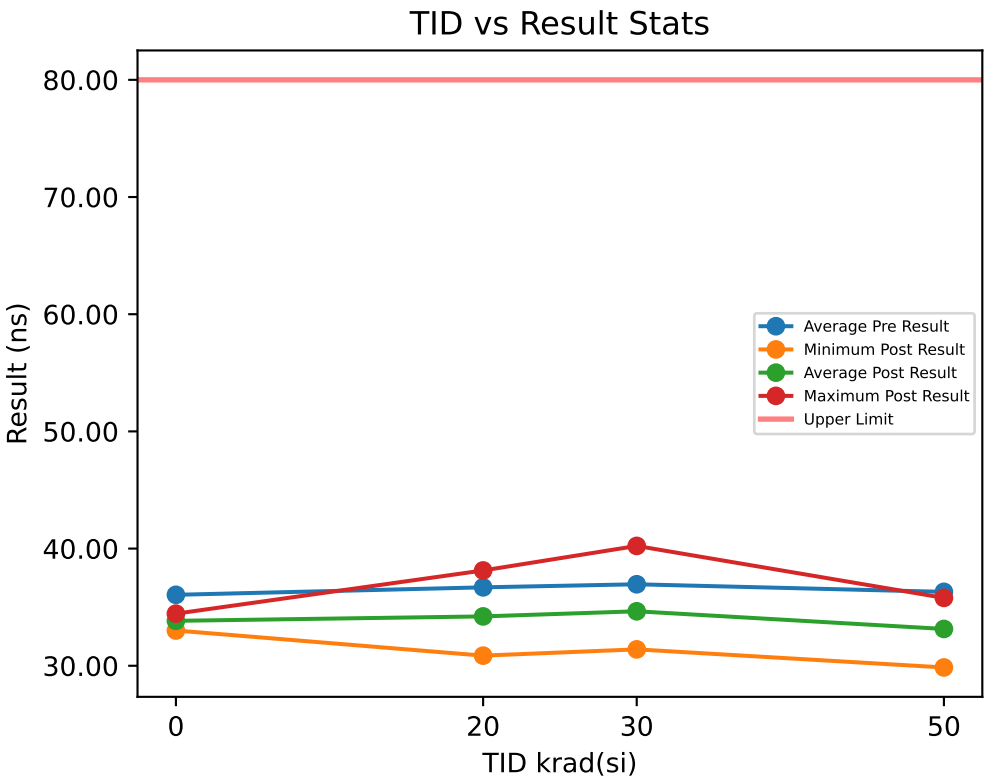
Test Results (Upper Limit = 14.0 (ns))

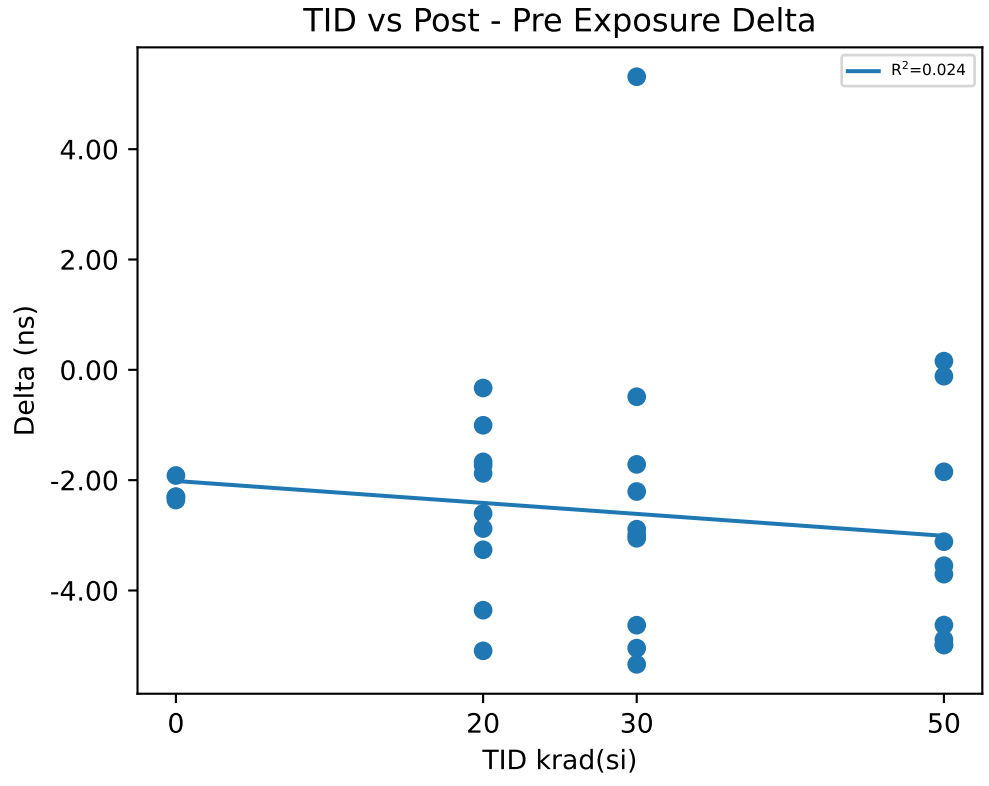
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	8.808	8.6403	-0.1677
2	20	Unbiased	8.8014	8.4843	-0.3171
3	50	Biased	8.2052	8.36	0.1548
4	30	Unbiased	8.4987	8.2348	-0.2639
5	50	Unbiased	8.8613	7.9563	-0.905
6	30	Biased	8.9112	7.8252	-1.086
7	50	Biased	8.316	8.3898	0.0738
8	30	Unbiased	8.4933	8.5058	0.0125
9	20	Unbiased	8.7693	8.0441	-0.7252
10	50	Biased	8.7839	7.7562	-1.0277
11	30	Biased	8.2213	7.834	-0.3873
12	0	Correlation	8.6175	7.7849	-0.8326
13	0	Correlation	8.8486	8.6979	-0.1507
14	50	Unbiased	8.8734	8.216	-0.6574
15	20	Biased	8.2771	7.8707	-0.4064
16	20	Unbiased	8.4789	8.7386	0.2597
17	20	Biased	8.8625	8.7049	-0.1576
18	20	Unbiased	8.9139	8.5271	-0.3868
19	20	Biased	8.2531	8.5677	0.3146
20	50	Unbiased	8.623	8.1806	-0.4424
21	0	Correlation	8.8078	8.5692	-0.2386
22	50	Unbiased	8.942	8.0655	-0.8765
23	0	Correlation	8.3398	8.6293	0.2895
24	20	Biased	8.5653	8.473	-0.0923
26	50	Biased	8.8966	8.6912	-0.2054
27	30	Unbiased	8.3002	8.246	-0.0542
28	30	Biased	8.562	8.5587	-0.0033
29	30	Unbiased	8.8651	8.4689	-0.3962
30	20	Biased	8.8433	7.9475	-0.8958
31	30	Unbiased	8.3119	8.7935	0.4816
33	30	Biased	8.9118	7.999	-0.9128
34	50	Unbiased	8.8446	8.3163	-0.5283
35	20	Unbiased	8.2074	7.7119	-0.4955
41	30	Biased	8.8388	8.0007	-0.8381

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	8.3398	8.6534	8.8486	0.23207	7.7849	8.4203	8.6979	0.42687	-0.8326	-0.2331	0.2895	0.46164
20	8.2074	8.5972	8.9139	0.27697	7.7119	8.307	8.7386	0.37459	-0.8958	-0.29024	0.3146	0.38681
30	8.2213	8.5914	8.9118	0.27081	7.8252	8.2467	8.7935	0.33046	-1.086	-0.34477	0.4816	0.4874
50	8.2052	8.7154	8.942	0.25577	7.7562	8.2572	8.6912	0.28918	-1.0277	-0.45818	0.1548	0.41511

Device Test: 25.1 TIMING|LEB/EN/5/5/0/0/5/500kHz//@T_LEB





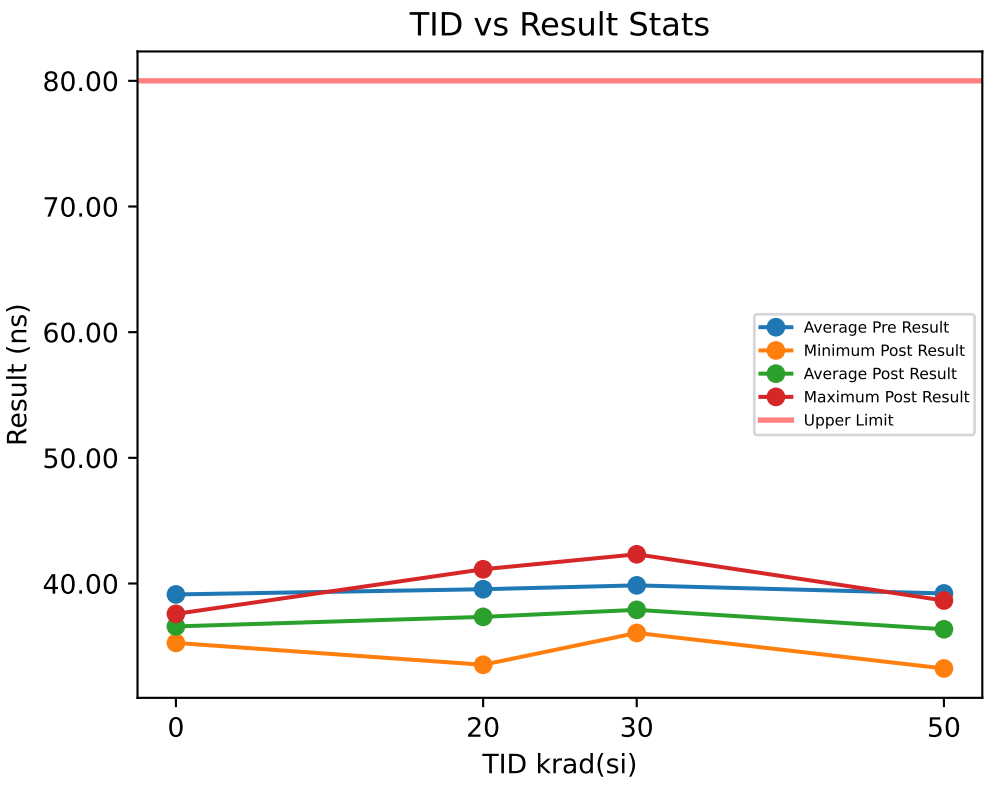
Test Results (Upper Limit = 80.0 (ns))

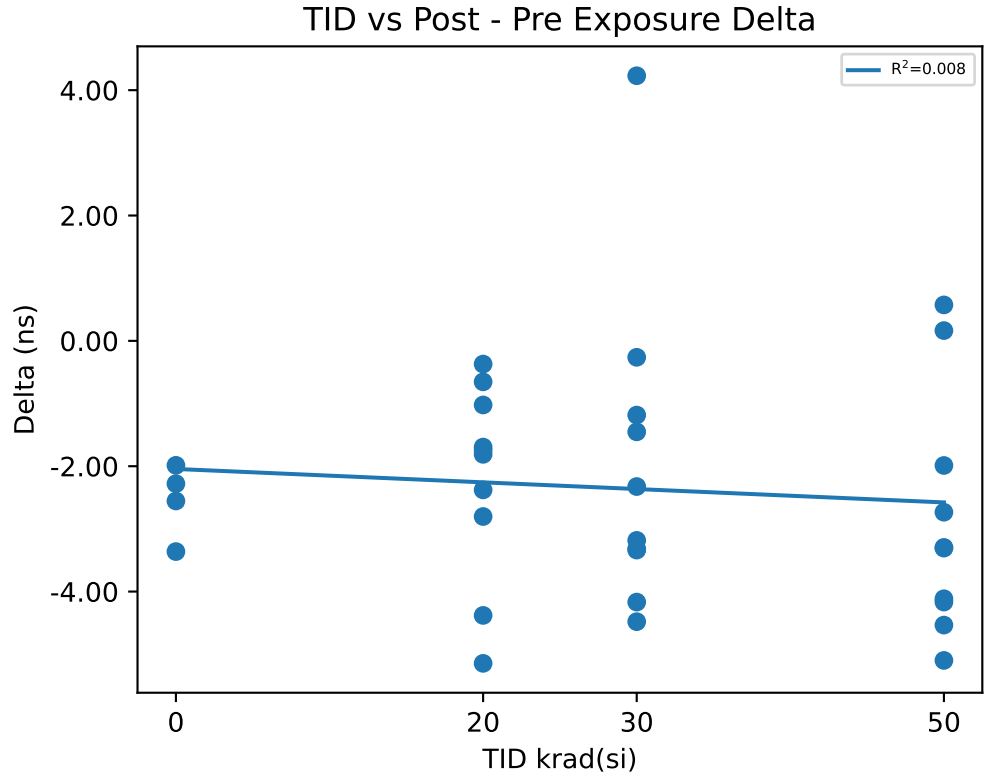
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	37.386	32.398	-4.9878
2	20	Unbiased	36.724	35.056	-1.6684
3	50	Biased	36.539	31.65	-4.8882
4	30	Unbiased	39.306	36.312	-2.9935
5	50	Unbiased	38.401	33.415	-4.9868
6	30	Biased	36.304	34.59	-1.7141
7	50	Biased	34.482	29.856	-4.6265
8	30	Unbiased	38.764	33.72	-5.0448
9	20	Unbiased	38.462	38.133	-0.3294
10	50	Biased	35.969	34.12	-1.8484
11	30	Biased	37.059	34.17	-2.8889
12	0	Correlation	34.925	33.009	-1.916
13	0	Correlation	36.7	34.396	-2.3042
14	50	Unbiased	35.635	35.792	0.1576
15	20	Biased	35.923	33.319	-2.6045
16	20	Unbiased	37.266	32.172	-5.0939
17	20	Biased	38.069	34.807	-3.2619
18	20	Unbiased	32.741	30.864	-1.8771
19	20	Biased	38.222	35.345	-2.8772
20	50	Unbiased	36.65	33.534	-3.1154
21	0	Correlation	35.785	33.485	-2.2999
22	50	Unbiased	35.425	35.309	-0.1158
23	0	Correlation	36.807	34.447	-2.361
24	20	Biased	37.259	32.902	-4.3571
26	50	Biased	35.804	32.1	-3.7039
27	30	Unbiased	36.105	35.617	-0.4882
28	30	Biased	36.739	31.4	-5.3392
29	30	Unbiased	37.294	32.664	-4.6295
30	20	Biased	35.661	34.656	-1.005
31	30	Unbiased	35.575	33.369	-2.2057
33	30	Biased	37.476	34.422	-3.054
34	50	Unbiased	36.787	33.237	-3.5504
35	20	Unbiased	36.599	34.867	-1.7317
41	30	Biased	34.913	40.226	5.3132

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	34.925	36.054	36.807	0.8816	33.009	33.834	34.447	0.70542	-2.361	-2.2203	-1.916	0.20475
20	32.741	36.693	38.462	1.6764	30.864	34.212	38.133	2.0064	-5.0939	-2.4806	-0.3294	1.4728
30	34.913	36.953	39.306	1.3524	31.4	34.649	40.226	2.4059	-5.3392	-2.3045	5.3132	3.0766
50	34.482	36.308	38.401	1.0995	29.856	33.141	35.792	1.7504	-4.9878	-3.1666	0.1576	1.951

Device Test: 25.4 TIMING|LEB/EN/12/12/0/0/5/500kHz//@T_LEB





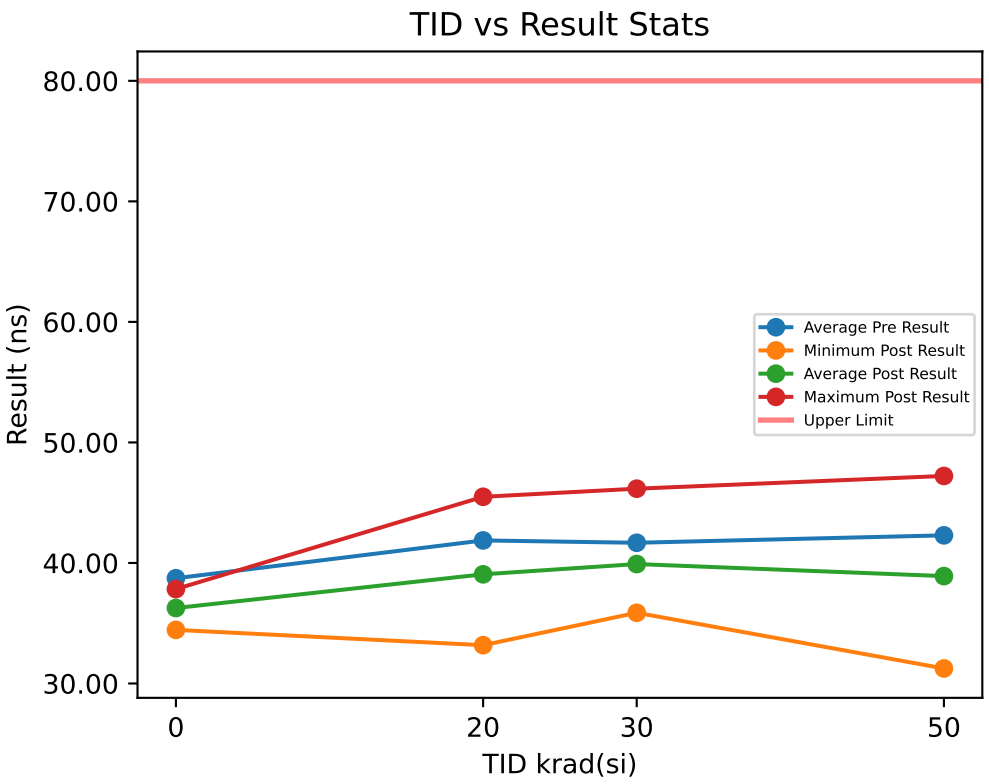
Test Results (Upper Limit = 80.0 (ns))

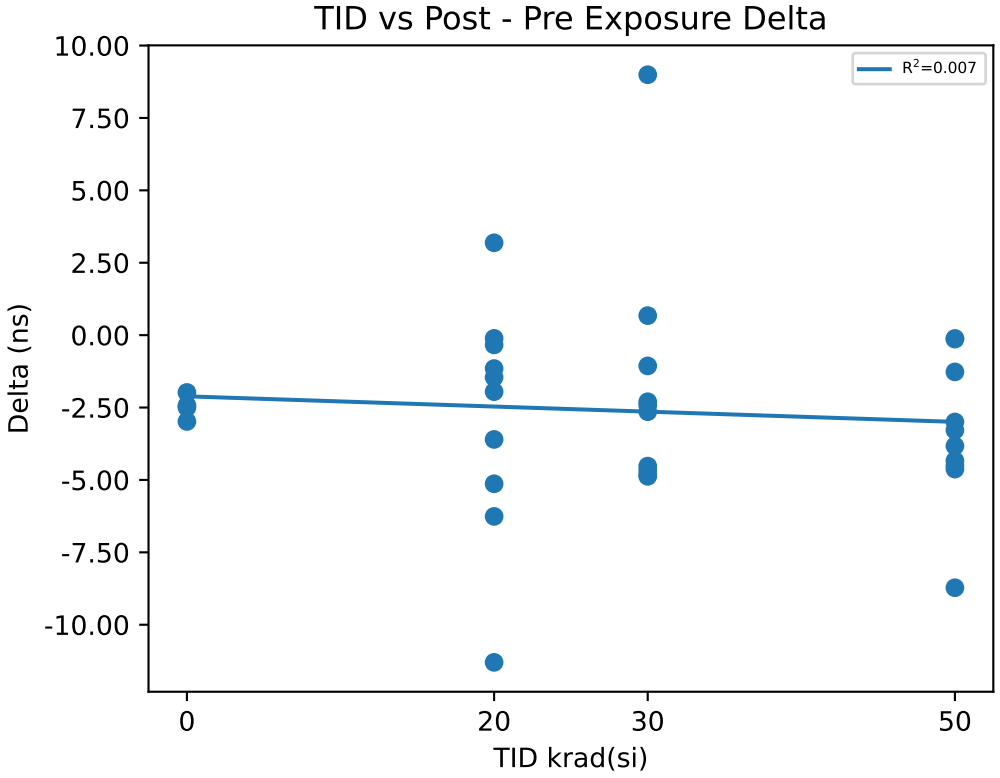
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	40.44	35.905	-4.5349
2	20	Unbiased	39.503	38.48	-1.0228
3	50	Biased	39.36	35.192	-4.1674
4	30	Unbiased	42.36	39.176	-3.1834
5	50	Unbiased	41.584	36.486	-5.0984
6	30	Biased	39.143	37.959	-1.1839
7	50	Biased	37.355	33.24	-4.1147
8	30	Unbiased	41.172	36.691	-4.4804
9	20	Unbiased	41.503	41.133	-0.3701
10	50	Biased	38.636	36.648	-1.988
11	30	Biased	39.67	37.346	-2.3243
12	0	Correlation	37.552	35.274	-2.2785
13	0	Correlation	39.569	37.583	-1.9858
14	50	Unbiased	38.073	38.647	0.574
15	20	Biased	38.355	36.544	-1.8105
16	20	Unbiased	40.373	35.228	-5.1455
17	20	Biased	40.785	37.983	-2.8026
18	20	Unbiased	35.227	33.533	-1.6947
19	20	Biased	41.17	38.792	-2.3778
20	50	Unbiased	39.805	36.509	-3.2956
21	0	Correlation	38.782	36.227	-2.5549
22	50	Unbiased	38.324	38.488	0.164
23	0	Correlation	40.617	37.255	-3.3619
24	20	Biased	40.235	35.854	-4.3805
26	50	Biased	38.831	35.525	-3.3066
27	30	Unbiased	38.899	38.637	-0.2622
28	30	Biased	39.482	36.165	-3.3174
29	30	Unbiased	40.235	36.067	-4.168
30	20	Biased	38.516	37.862	-0.6538
31	30	Unbiased	38.309	36.857	-1.4517
33	30	Biased	41.15	37.811	-3.3382
34	50	Unbiased	39.688	36.953	-2.7341
35	20	Unbiased	39.781	38.036	-1.7451
41	30	Biased	38.095	42.325	4.2303

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	37.552	39.13	40.617	1.2928	35.274	36.585	37.583	1.0476	-3.3619	-2.5453	-1.9858	0.59193
20	35.227	39.545	41.503	1.8363	33.533	37.345	41.133	2.1282	-5.1455	-2.2003	-0.3701	1.5479
30	38.095	39.851	42.36	1.3706	36.067	37.903	42.325	1.8558	-4.4804	-1.9479	4.2303	2.553
50	37.355	39.209	41.584	1.2358	33.24	36.359	38.647	1.5717	-5.0984	-2.8502	0.574	1.9207

Device Test: 25.7 TIMING|LEB/EN/14/14/0/0/5/500kHz//@T_LEB





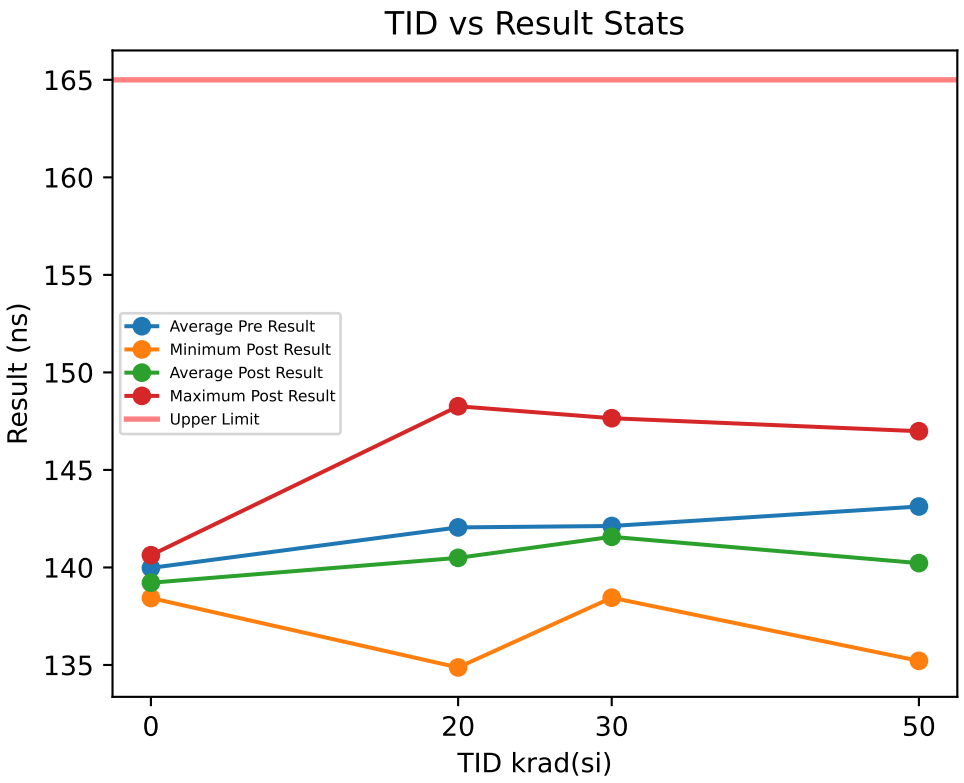
Test Results (Upper Limit = 80.0 (ns))

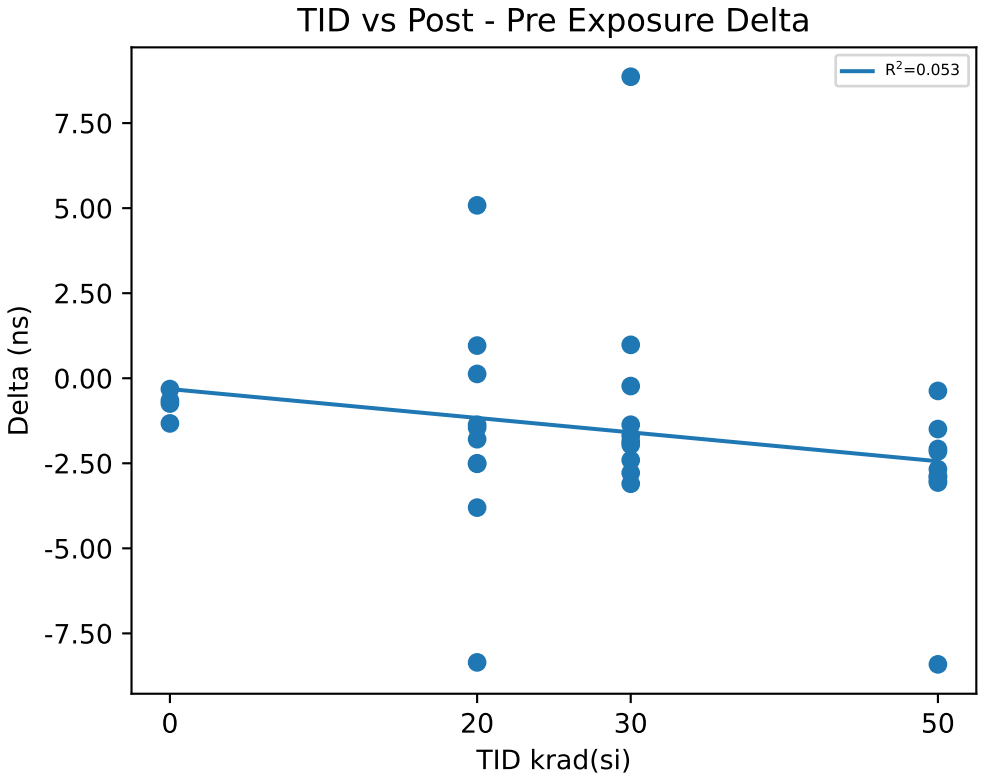
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	40.705	36.37	-4.3353
2	20	Unbiased	40.031	38.574	-1.4567
3	50	Biased	40.42	36.593	-3.8276
4	30	Unbiased	44.769	39.947	-4.8214
5	50	Unbiased	49.01	44.384	-4.6258
6	30	Biased	40.107	40.78	0.6735
7	50	Biased	35.754	31.247	-4.5063
8	30	Unbiased	43.014	38.139	-4.875
9	20	Unbiased	43.653	42.499	-1.1536
10	50	Biased	47.221	38.498	-8.7224
11	30	Biased	45.411	42.767	-2.6438
12	0	Correlation	37.428	34.448	-2.9806
13	0	Correlation	38.671	36.692	-1.9791
14	50	Unbiased	45.225	45.087	-0.1376
15	20	Biased	42.239	35.979	-6.2598
16	20	Unbiased	44.476	33.177	-11.299
17	20	Biased	42.301	45.49	3.1887
18	20	Unbiased	39.434	37.482	-1.9515
19	20	Biased	44.481	40.879	-3.602
20	50	Unbiased	39.223	35.941	-3.2816
21	0	Correlation	38.57	36.074	-2.496
22	50	Unbiased	47.334	47.218	-0.1153
23	0	Correlation	40.259	37.834	-2.4246
24	20	Biased	41.146	36.013	-5.1325
26	50	Biased	37.06	35.79	-1.2693
27	30	Unbiased	40.674	39.611	-1.0624
28	30	Biased	42.624	37.947	-4.6764
29	30	Unbiased	43.15	38.627	-4.5224
30	20	Biased	40.888	40.777	-0.1113
31	30	Unbiased	38.167	35.867	-2.2999
33	30	Biased	41.665	39.243	-2.4213
34	50	Unbiased	40.964	37.965	-2.9987
35	20	Unbiased	40.046	39.709	-0.3369
41	30	Biased	37.17	46.162	8.9918

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	37.428	38.732	40.259	1.1634	34.448	36.262	37.834	1.4123	-2.9806	-2.4701	-1.9791	0.41005
20	39.434	41.869	44.481	1.8632	33.177	39.058	45.49	3.5895	-11.299	-2.8115	3.1887	4.0095
30	37.17	41.675	45.411	2.6761	35.867	39.909	46.162	2.8581	-4.875	-1.7657	8.9918	4.1996
50	35.754	42.291	49.01	4.604	31.247	38.909	47.218	5.0254	-8.7224	-3.382	-0.1153	2.5442

Device Test: 26.1 TIMING|MIN/OUT/4.5/4.5/0/0/4.5/500kHz//@TON_MIN





Test Results (Upper Limit = 165.0 (ns))

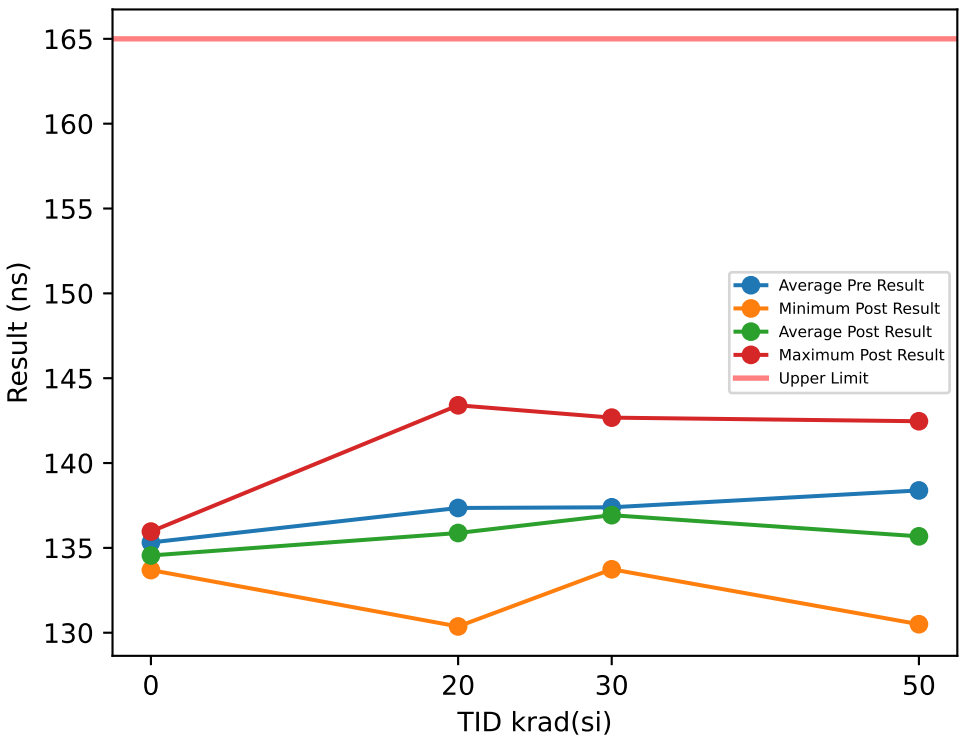
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	138.6	137.11	-1.4935
2	20	Unbiased	140.38	138.59	-1.7926
3	50	Biased	139.78	137.7	-2.0783
4	30	Unbiased	142.53	139.43	-3.1009
5	50	Unbiased	149.89	146.99	-2.9028
6	30	Biased	143.38	144.37	0.9817
7	50	Biased	137.88	135.21	-2.6733
8	30	Unbiased	141.33	139.64	-1.6894
9	20	Unbiased	142.13	140.68	-1.4546
10	50	Biased	148.28	139.87	-8.4103
11	30	Biased	145.66	143.8	-1.8581
12	0	Correlation	139.25	138.93	-0.318
13	0	Correlation	139.09	138.43	-0.654
14	50	Unbiased	146.01	143.86	-2.1505
15	20	Biased	143.05	139.25	-3.8032
16	20	Unbiased	143.23	134.87	-8.3524
17	20	Biased	143.18	148.26	5.0824
18	20	Unbiased	141.76	140.4	-1.3666
19	20	Biased	143.32	140.82	-2.4993
20	50	Unbiased	139.95	136.89	-3.066
21	0	Correlation	139.61	138.87	-0.7439
22	50	Unbiased	149.28	146.28	-3.0078
23	0	Correlation	141.96	140.63	-1.3279
24	20	Biased	141.43	138.92	-2.5149
26	50	Biased	140.03	139.66	-0.373
27	30	Unbiased	142.42	140.47	-1.9576
28	30	Biased	142.68	139.9	-2.7823
29	30	Unbiased	142.24	139.84	-2.4064
30	20	Biased	142.9	143.03	0.1268
31	30	Unbiased	139.82	138.45	-1.3667
33	30	Biased	142.4	142.17	-0.2294
34	50	Unbiased	141.54	138.67	-2.8736
35	20	Unbiased	139.14	140.1	0.9599
41	30	Biased	138.79	147.65	8.8628

Test Statistics (ns)

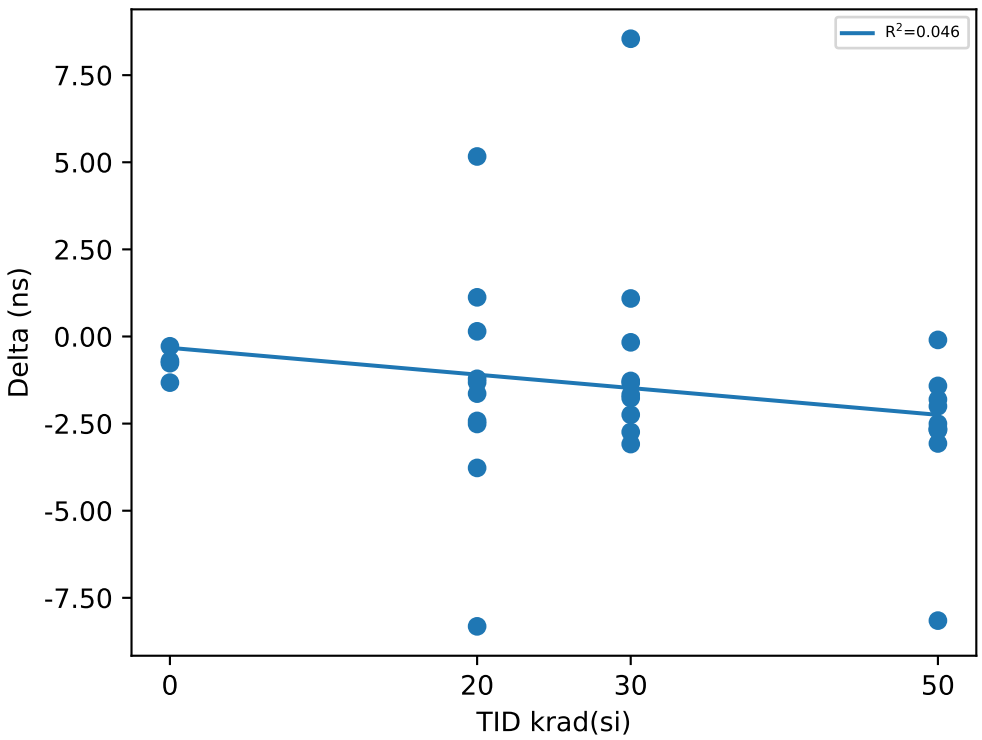
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	139.09	139.98	141.96	1.338	138.43	139.22	140.63	0.96777	-1.3279	-0.76095	-0.318	0.42007
20	139.14	142.05	143.32	1.4041	134.87	140.49	148.26	3.438	-8.3524	-1.5615	5.0824	3.4381
30	138.79	142.13	145.66	1.88	138.45	141.57	147.65	2.8902	-3.1009	-0.55463	8.8628	3.5221
50	137.88	143.13	149.89	4.7121	135.21	140.22	146.99	4.0924	-8.4103	-2.9029	-0.373	2.1096

Device Test: 26.2 TIMING|MIN/OUT/5/5/0/0/5/500kHz//@TON_MIN

TID vs Result Stats



TID vs Post - Pre Exposure Delta



Test Results (Upper Limit = 165.0 (ns))

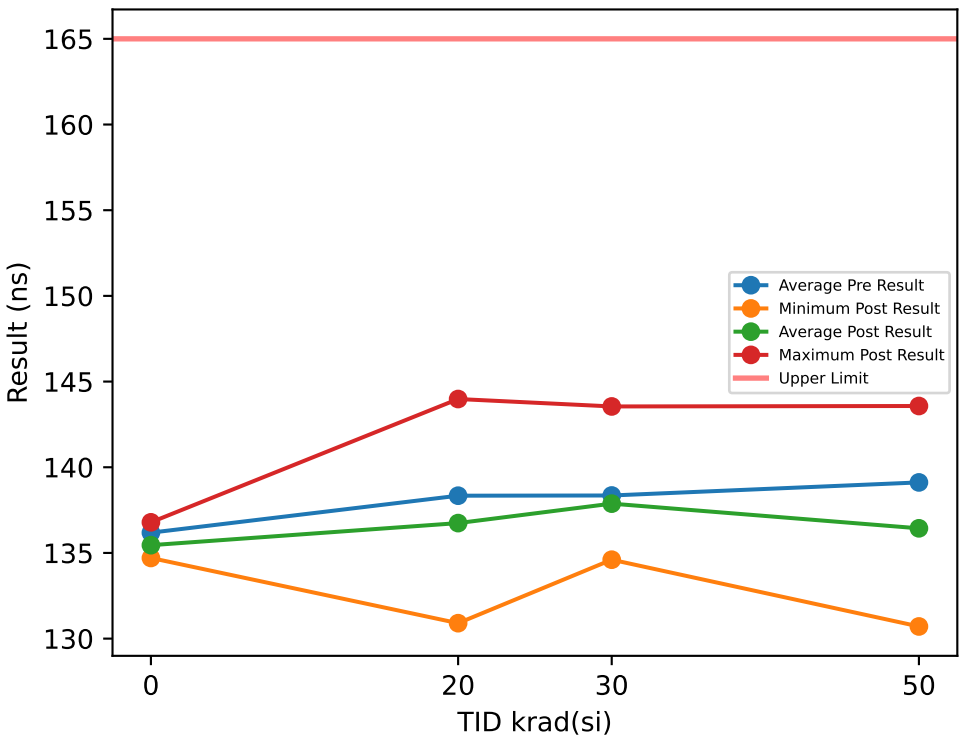
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	134.1	132.68	-1.4179
2	20	Unbiased	135.76	134.12	-1.6397
3	50	Biased	135.24	133.24	-2.0022
4	30	Unbiased	138.06	134.98	-3.0873
5	50	Unbiased	144.97	142.46	-2.5031
6	30	Biased	138.5	139.59	1.0908
7	50	Biased	133.19	130.5	-2.6862
8	30	Unbiased	136.78	135.1	-1.6718
9	20	Unbiased	137.36	136.04	-1.3172
10	50	Biased	143.57	135.42	-8.1541
11	30	Biased	140.62	139.35	-1.2757
12	0	Correlation	134.63	134.35	-0.281
13	0	Correlation	134.39	133.69	-0.6997
14	50	Unbiased	141.22	139.41	-1.8071
15	20	Biased	138.39	134.61	-3.772
16	20	Unbiased	138.69	130.37	-8.3188
17	20	Biased	138.24	143.4	5.1662
18	20	Unbiased	136.98	135.77	-1.2144
19	20	Biased	138.62	136.2	-2.4228
20	50	Unbiased	135.3	132.23	-3.0704
21	0	Correlation	134.97	134.21	-0.7665
22	50	Unbiased	144.42	141.74	-2.6738
23	0	Correlation	137.29	135.96	-1.3241
24	20	Biased	136.76	134.24	-2.5106
26	50	Biased	135.2	135.1	-0.0982
27	30	Unbiased	137.68	135.92	-1.7658
28	30	Biased	137.91	135.17	-2.7411
29	30	Unbiased	137.55	135.31	-2.2464
30	20	Biased	138.04	138.19	0.1484
31	30	Unbiased	135.07	133.74	-1.3305
33	30	Biased	137.61	137.44	-0.1674
34	50	Unbiased	136.65	134.02	-2.6311
35	20	Unbiased	134.69	135.81	1.1239
41	30	Biased	134.13	142.68	8.5451

Test Statistics (ns)

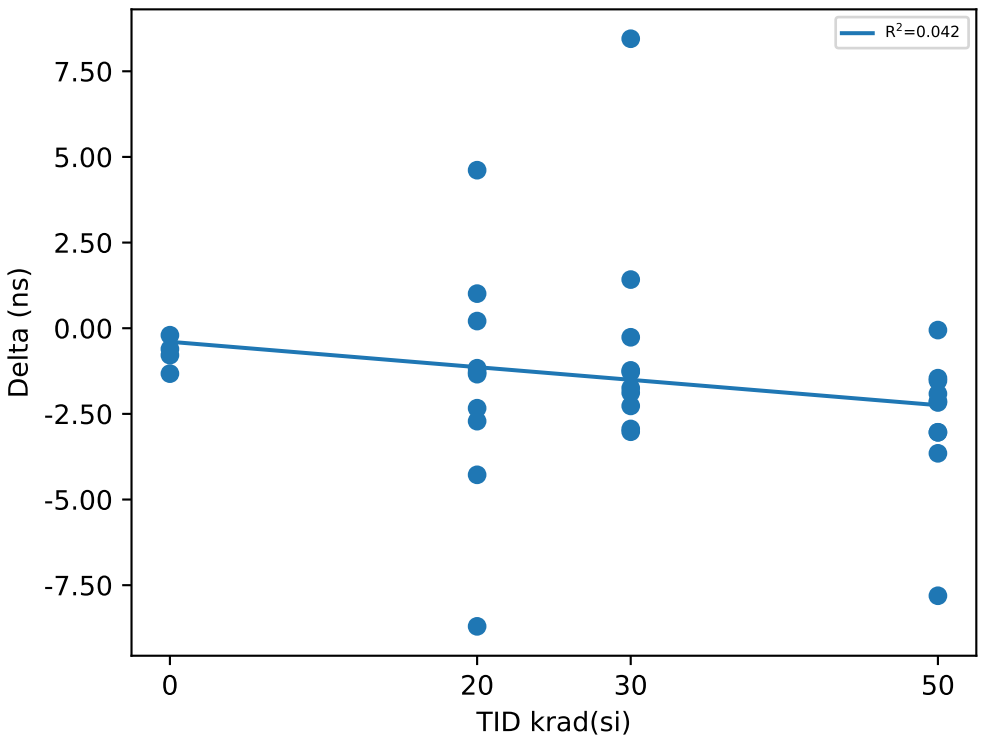
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	134.39	135.32	137.29	1.332	133.69	134.55	135.96	0.98126	-1.3241	-0.76782	-0.281	0.4286
20	134.69	137.35	138.69	1.3272	130.37	135.88	143.4	3.3307	-8.3188	-1.4757	5.1662	3.4593
30	134.13	137.39	140.62	1.7938	133.74	136.93	142.68	2.7945	-3.0873	-0.46501	8.5451	3.3908
50	133.19	138.39	144.97	4.6258	130.5	135.68	142.46	4.1303	-8.1541	-2.7044	-0.0982	2.0983

Device Test: 26.3 TIMING|MIN/OUT/12/12/0/0/5/500kHz//@TON_MIN

TID vs Result Stats



TID vs Post - Pre Exposure Delta



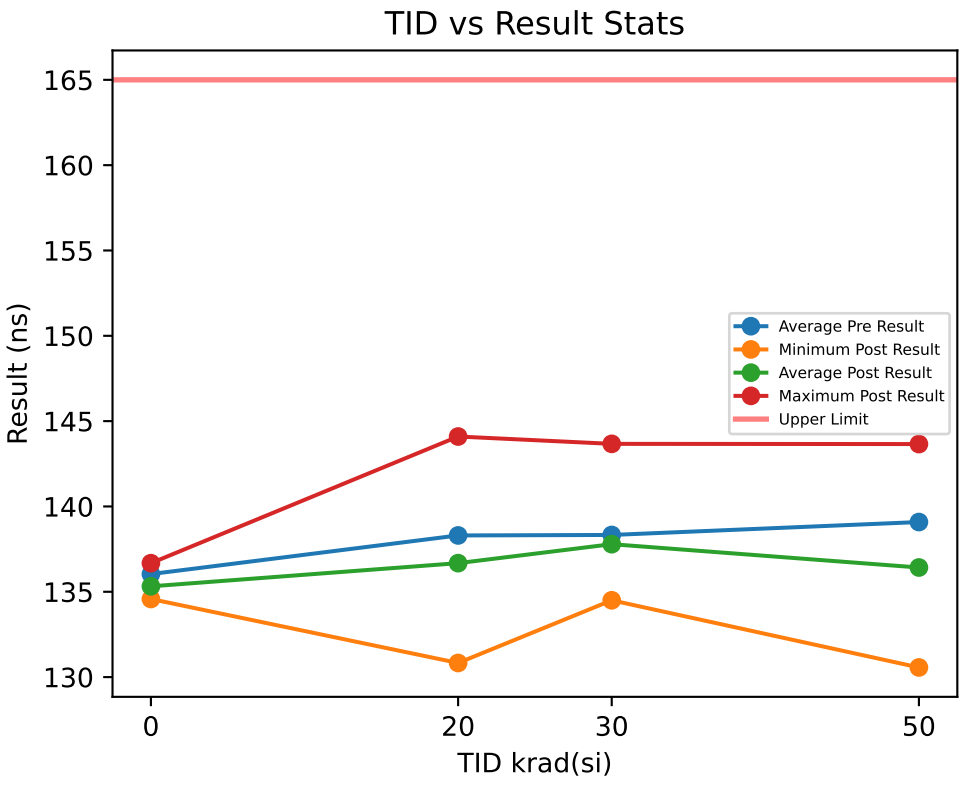
Test Results (Upper Limit = 165.0 (ns))

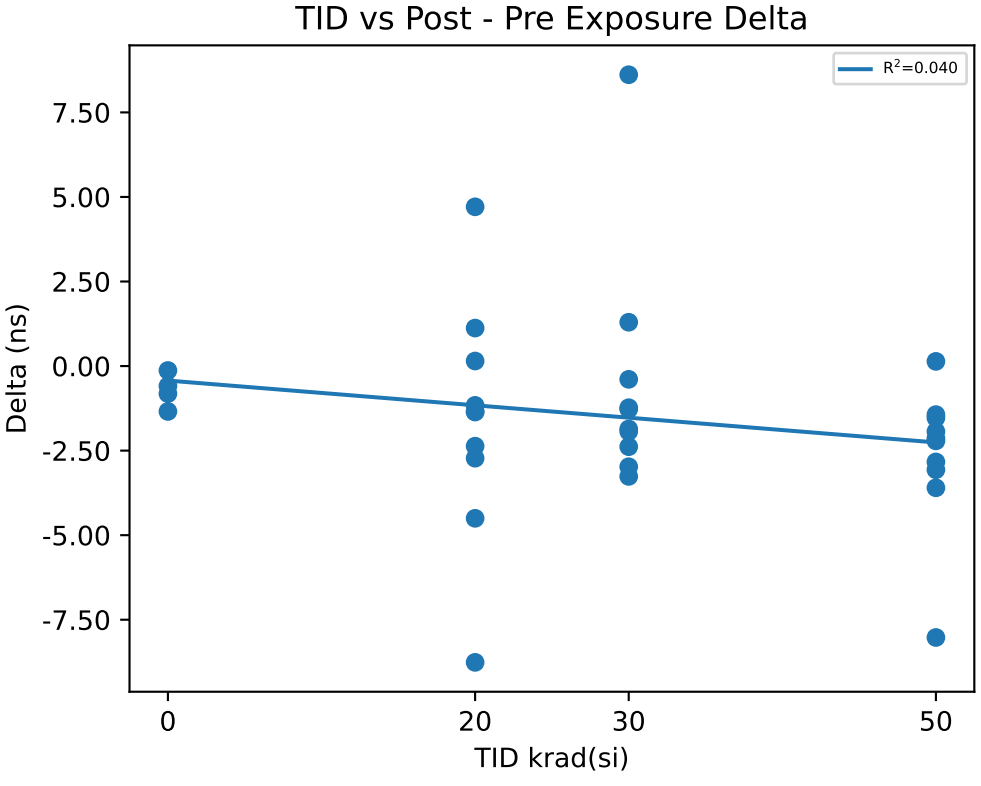
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	135.07	133.54	-1.5314
2	20	Unbiased	136.57	135.23	-1.3413
3	50	Biased	136.13	134	-2.1301
4	30	Unbiased	139.05	136.02	-3.0213
5	50	Unbiased	145.49	143.57	-1.9126
6	30	Biased	139.23	140.65	1.4201
7	50	Biased	133.75	130.71	-3.0372
8	30	Unbiased	137.71	135.96	-1.7455
9	20	Unbiased	138.62	137.34	-1.2834
10	50	Biased	144.24	136.43	-7.8087
11	30	Biased	141.7	140.47	-1.2303
12	0	Correlation	135.51	135.31	-0.2034
13	0	Correlation	135.31	134.71	-0.607
14	50	Unbiased	142.1	140.65	-1.4576
15	20	Biased	139.73	135.45	-4.2785
16	20	Unbiased	139.6	130.9	-8.7018
17	20	Biased	139.37	143.98	4.6127
18	20	Unbiased	137.73	136.56	-1.167
19	20	Biased	139.67	137.34	-2.3342
20	50	Unbiased	136.07	132.42	-3.6513
21	0	Correlation	135.79	135	-0.7863
22	50	Unbiased	144.78	142.61	-2.1673
23	0	Correlation	138.11	136.79	-1.3256
24	20	Biased	137.61	134.9	-2.7129
26	50	Biased	135.97	135.92	-0.0541
27	30	Unbiased	138.71	136.83	-1.8827
28	30	Biased	138.8	135.86	-2.9398
29	30	Unbiased	138.68	136.41	-2.2676
30	20	Biased	138.91	139.12	0.209
31	30	Unbiased	135.88	134.61	-1.2771
33	30	Biased	138.67	138.4	-0.2641
34	50	Unbiased	137.55	134.52	-3.0373
35	20	Unbiased	135.59	136.6	1.0099
41	30	Biased	135.1	143.55	8.4496

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	135.31	136.18	138.11	1.3009	134.71	135.45	136.79	0.92306	-1.3256	-0.73058	-0.2034	0.4656
20	135.59	138.34	139.73	1.428	130.9	136.74	143.98	3.3392	-8.7018	-1.5988	4.6127	3.4709
30	135.1	138.35	141.7	1.8294	134.61	137.88	143.55	2.8285	-3.0213	-0.47587	8.4496	3.3972
50	133.75	139.12	145.49	4.5163	130.71	136.44	143.57	4.3978	-7.8087	-2.6788	-0.0541	2.0647

Device Test: 26.4 TIMING|MIN/OUT/14/14/0/0/5/500kHz//@TON_MIN





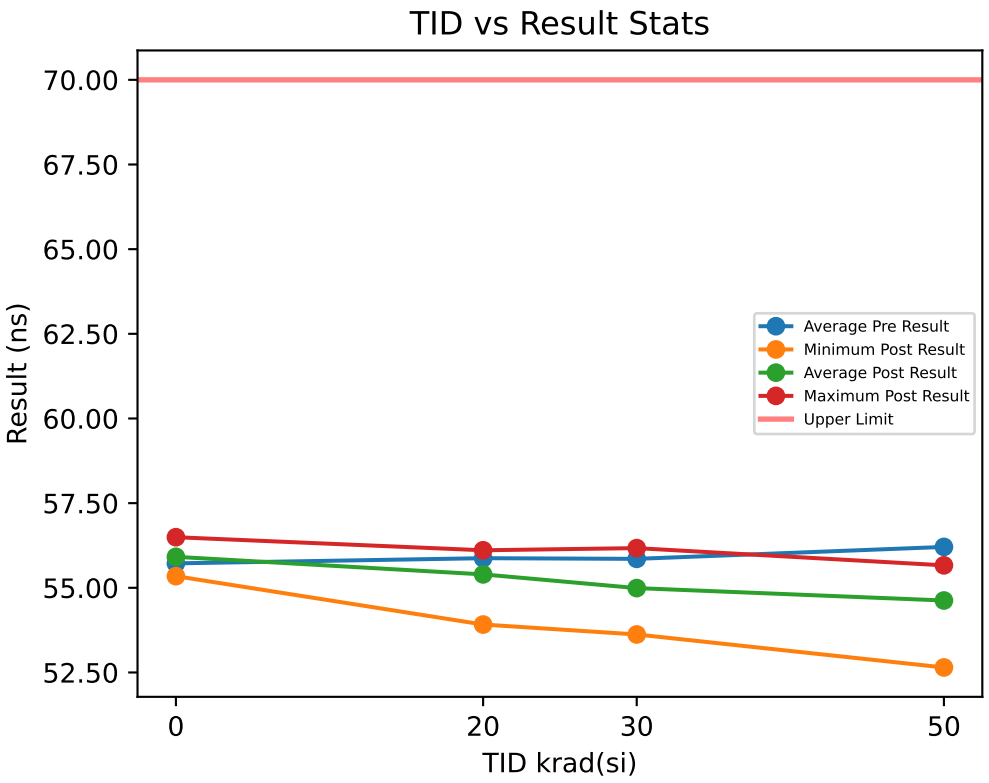
Test Results (Upper Limit = 165.0 (ns))

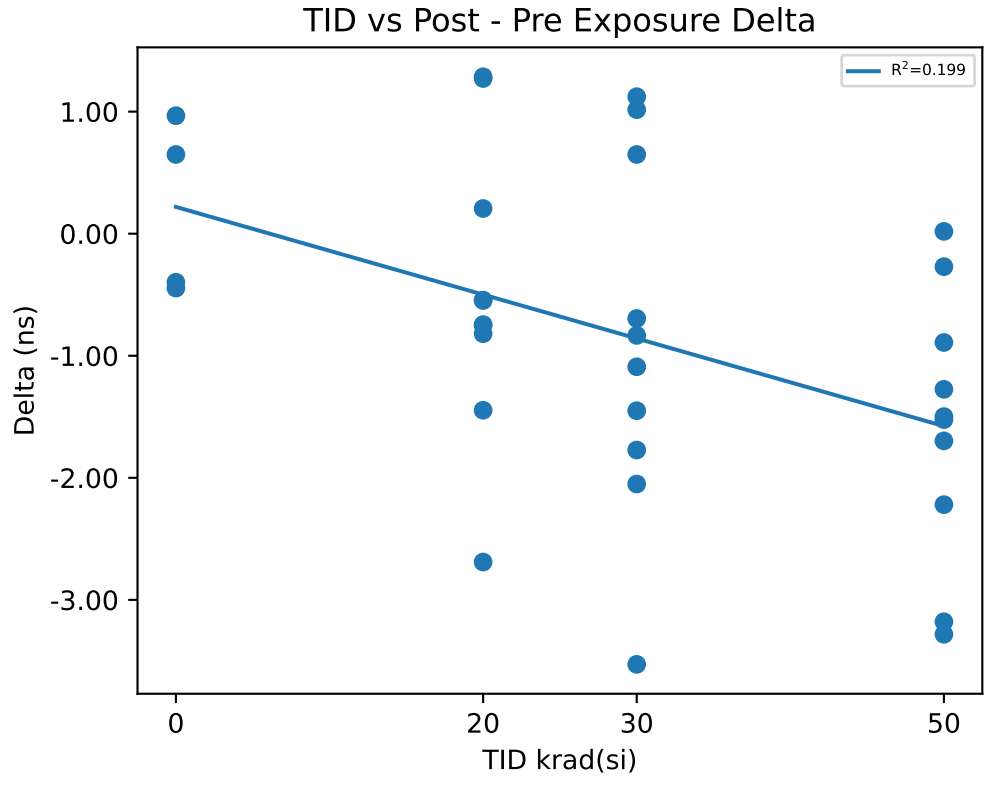
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	134.96	133.43	-1.5312
2	20	Unbiased	136.51	135.17	-1.3417
3	50	Biased	136.01	133.87	-2.1394
4	30	Unbiased	139.2	135.94	-3.2626
5	50	Unbiased	145.59	143.66	-1.9341
6	30	Biased	139.2	140.49	1.2958
7	50	Biased	133.63	130.57	-3.0657
8	30	Unbiased	137.7	135.84	-1.8602
9	20	Unbiased	138.64	137.28	-1.3598
10	50	Biased	144.31	136.29	-8.0251
11	30	Biased	141.72	140.49	-1.2313
12	0	Correlation	135.26	135.13	-0.1307
13	0	Correlation	135.17	134.58	-0.5892
14	50	Unbiased	142.16	140.73	-1.4353
15	20	Biased	139.75	135.25	-4.5015
16	20	Unbiased	139.59	130.83	-8.7605
17	20	Biased	139.39	144.1	4.7084
18	20	Unbiased	137.64	136.48	-1.1618
19	20	Biased	139.69	137.32	-2.3686
20	50	Unbiased	135.92	132.32	-3.5992
21	0	Correlation	135.71	134.89	-0.8149
22	50	Unbiased	144.89	142.68	-2.212
23	0	Correlation	138.02	136.68	-1.3414
24	20	Biased	137.51	134.79	-2.7246
26	50	Biased	135.89	136.03	0.1385
27	30	Unbiased	138.63	136.69	-1.9341
28	30	Biased	138.73	135.75	-2.9771
29	30	Unbiased	138.67	136.28	-2.384
30	20	Biased	138.86	139.01	0.1493
31	30	Unbiased	135.77	134.5	-1.2732
33	30	Biased	138.63	138.23	-0.3928
34	50	Unbiased	137.49	134.65	-2.8344
35	20	Unbiased	135.43	136.56	1.1235
41	30	Biased	135.05	143.67	8.6136

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	135.17	136.04	138.02	1.3402	134.58	135.32	136.68	0.9321	-1.3414	-0.71905	-0.1307	0.50316
20	135.43	138.3	139.75	1.483	130.83	136.68	144.1	3.3902	-8.7605	-1.6237	4.7084	3.5297
30	135.05	138.33	141.72	1.8594	134.5	137.79	143.67	2.8874	-3.2626	-0.54059	8.6136	3.4743
50	133.63	139.09	145.59	4.6171	130.57	136.42	143.66	4.4718	-8.0251	-2.6638	0.1385	2.1465

Device Test: 26.5 TIMING|EXT/OUT/4.5/4.5/0/0/4.5/500kHz//@T_OFF_EXTENDER





Test Results (Upper Limit = 70.0 (ns))

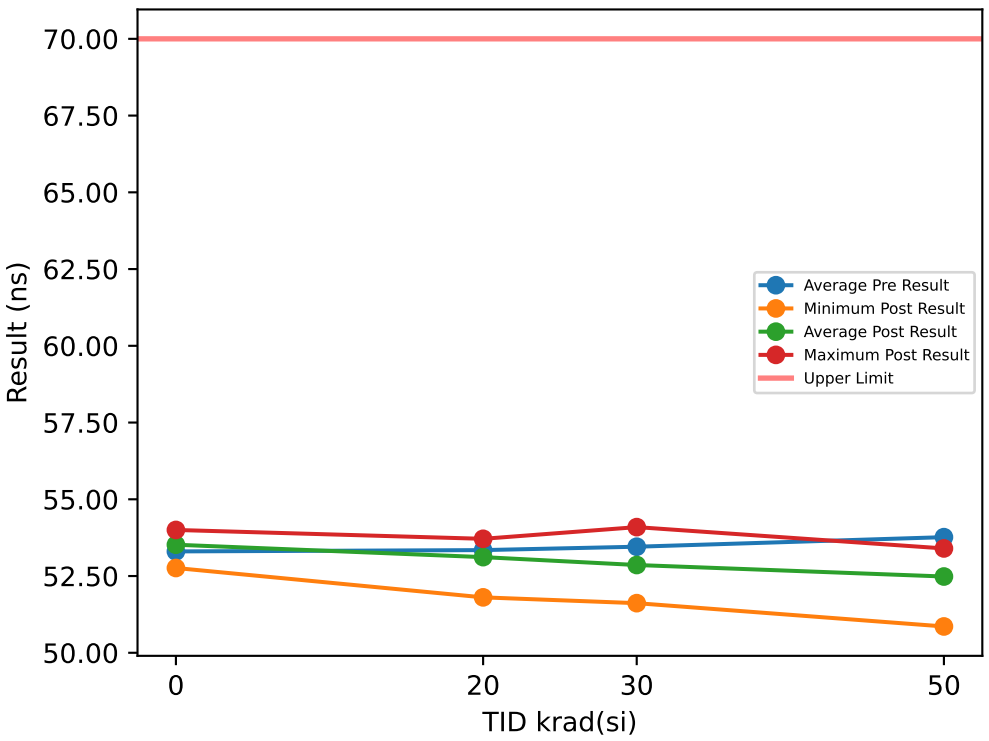
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	56.148	55.256	-0.8913
2	20	Unbiased	56.611	55.792	-0.8194
3	50	Biased	55.645	55.664	0.0187
4	30	Unbiased	54.548	53.715	-0.8335
5	50	Unbiased	56.822	54.602	-2.2196
6	30	Biased	56.28	54.83	-1.4503
7	50	Biased	55.295	55.025	-0.2702
8	30	Unbiased	54.709	55.831	1.1223
9	20	Unbiased	56.606	53.916	-2.6899
10	50	Biased	56.565	54.867	-1.6974
11	30	Biased	55.826	55.131	-0.6947
12	0	Correlation	54.377	55.344	0.9668
13	0	Correlation	56.063	55.617	-0.4455
14	50	Unbiased	57.457	54.278	-3.1792
15	20	Biased	55.827	55.282	-0.5443
16	20	Unbiased	54.03	55.301	1.2712
17	20	Biased	56.393	55.648	-0.7446
18	20	Unbiased	56.117	55.365	-0.7522
19	20	Biased	55.803	56.009	0.2064
20	50	Unbiased	54.171	52.648	-1.5232
21	0	Correlation	56.892	56.494	-0.3978
22	50	Unbiased	56.885	53.603	-3.2819
23	0	Correlation	55.555	56.204	0.649
24	20	Biased	54.823	56.108	1.2858
26	50	Biased	56.454	55.179	-1.2749
27	30	Unbiased	55.673	53.622	-2.0508
28	30	Biased	54.651	55.667	1.016
29	30	Unbiased	56.929	55.839	-1.0902
30	20	Biased	56.506	55.059	-1.4464
31	30	Unbiased	55.523	56.172	0.6488
33	30	Biased	56.87	55.098	-1.7723
34	50	Unbiased	56.629	55.131	-1.4982
35	20	Unbiased	56.03	55.483	-0.5468
41	30	Biased	57.541	54.013	-3.5282

Test Statistics (ns)

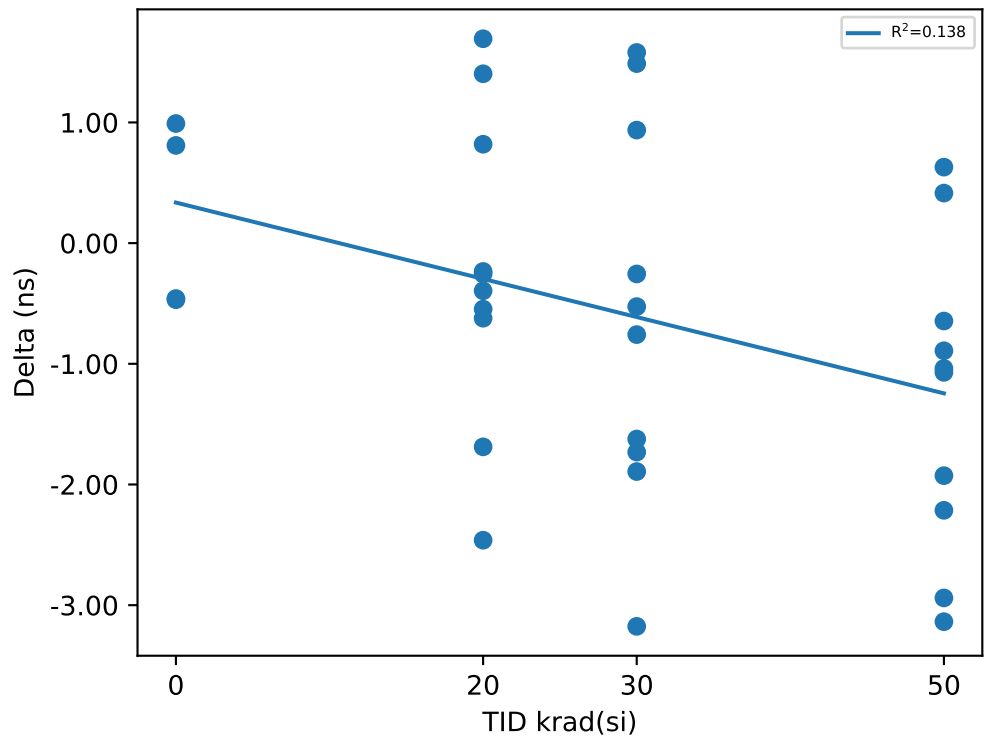
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	54.377	55.722	56.892	1.0523	55.344	55.915	56.494	0.5273	-0.4455	0.19313	0.9668	0.7219
20	54.03	55.875	56.611	0.83967	53.916	55.397	56.108	0.61817	-2.6899	-0.47802	1.2858	1.1898
30	54.548	55.855	57.541	1.0447	53.622	54.992	56.172	0.93046	-3.5282	-0.86329	1.1223	1.4729
50	54.171	56.207	57.457	0.94652	52.648	54.625	55.664	0.90258	-3.2819	-1.5817	0.0187	1.0917

Device Test: 26.7 TIMING|EXT/OUT/14/14/0/0/5/500kHz//@T_OFF_EXTENDER

TID vs Result Stats



TID vs Post - Pre Exposure Delta



Test Results (Upper Limit = 70.0 (ns))

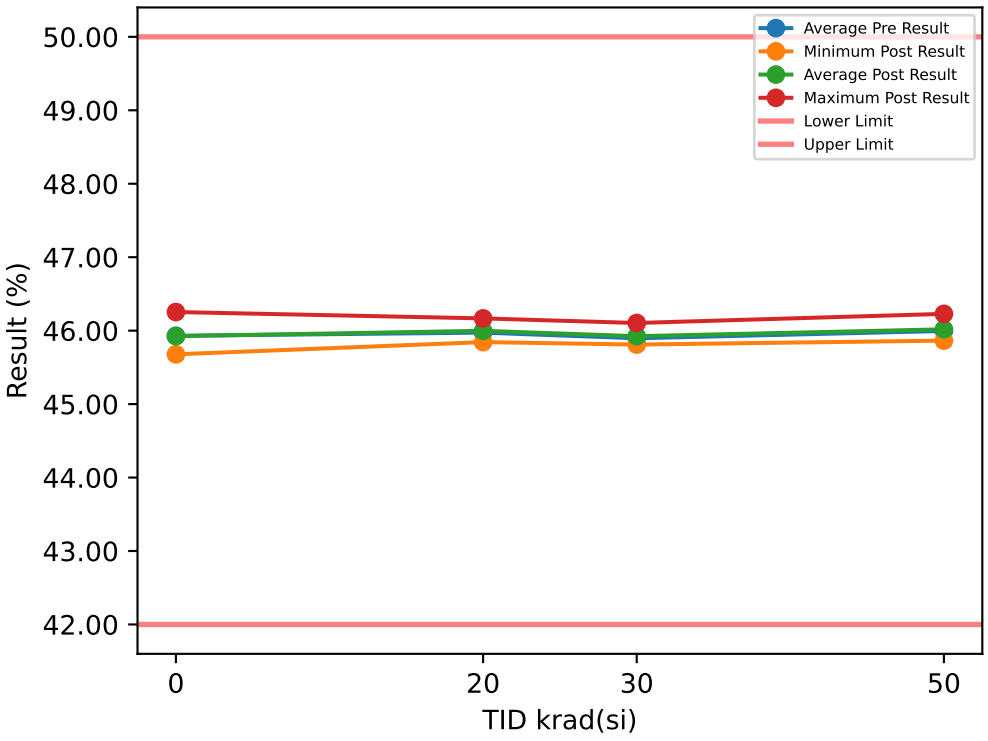
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	54.154	53.084	-1.0707
2	20	Unbiased	54.164	53.617	-0.5469
3	50	Biased	52.985	53.399	0.4147
4	30	Unbiased	52.142	51.616	-0.526
5	50	Unbiased	54.419	52.492	-1.9268
6	30	Biased	54.214	52.321	-1.8927
7	50	Biased	52.499	53.129	0.6296
8	30	Unbiased	52.303	53.79	1.4875
9	20	Unbiased	54.267	51.805	-2.4617
10	50	Biased	54.481	52.267	-2.214
11	30	Biased	53.197	52.942	-0.2554
12	0	Correlation	51.952	52.762	0.8096
13	0	Correlation	53.899	53.43	-0.4688
14	50	Unbiased	54.965	51.829	-3.1367
15	20	Biased	53.255	53.02	-0.2349
16	20	Unbiased	51.855	53.258	1.4033
17	20	Biased	54.022	53.4	-0.6222
18	20	Unbiased	53.546	53.151	-0.3948
19	20	Biased	52.868	53.687	0.8193
20	50	Unbiased	51.503	50.858	-0.6454
21	0	Correlation	54.461	54.001	-0.4593
22	50	Unbiased	54.562	51.622	-2.94
23	0	Correlation	52.897	53.888	0.991
24	20	Biased	52.019	53.713	1.6935
26	50	Biased	53.932	53.04	-0.8917
27	30	Unbiased	53.287	51.664	-1.6232
28	30	Biased	52.049	53.629	1.5798
29	30	Unbiased	54.709	53.951	-0.758
30	20	Biased	54.422	52.734	-1.6881
31	30	Unbiased	53.157	54.093	0.9366
33	30	Biased	54.334	52.602	-1.7317
34	50	Unbiased	54.163	53.124	-1.0384
35	20	Unbiased	53.031	52.776	-0.2552
41	30	Biased	55.16	51.984	-3.1755

Test Statistics (ns)

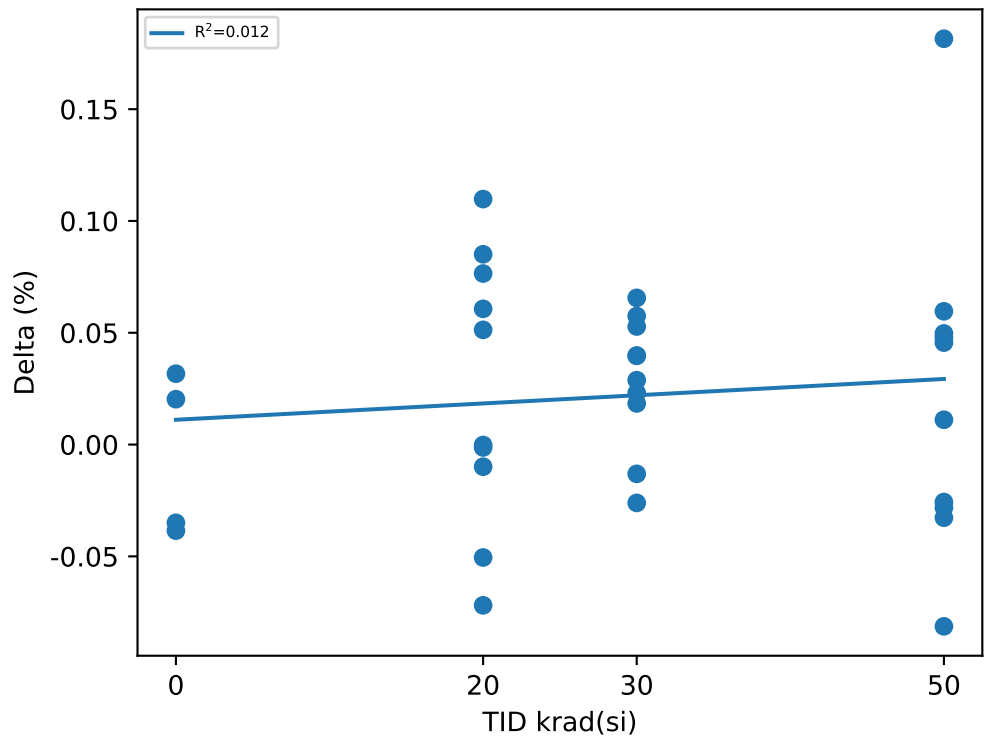
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	51.952	53.302	54.461	1.1083	52.762	53.52	54.001	0.56255	-0.4688	0.21812	0.991	0.79119
20	51.855	53.345	54.422	0.91231	51.805	53.116	53.713	0.57959	-2.4617	-0.22877	1.6935	1.2848
30	52.049	53.455	55.16	1.1075	51.616	52.859	54.093	0.95892	-3.1755	-0.59586	1.5798	1.5724
50	51.503	53.766	54.965	1.0895	50.858	52.484	53.399	0.8298	-3.1367	-1.2819	0.6296	1.2766

Device Test: 27.17 LEVEL|DCL/OUT/4.5/4.5/0/0/4.5/100kHz//@MAX_DCL_50

TID vs Result Stats



TID vs Post - Pre Exposure Delta



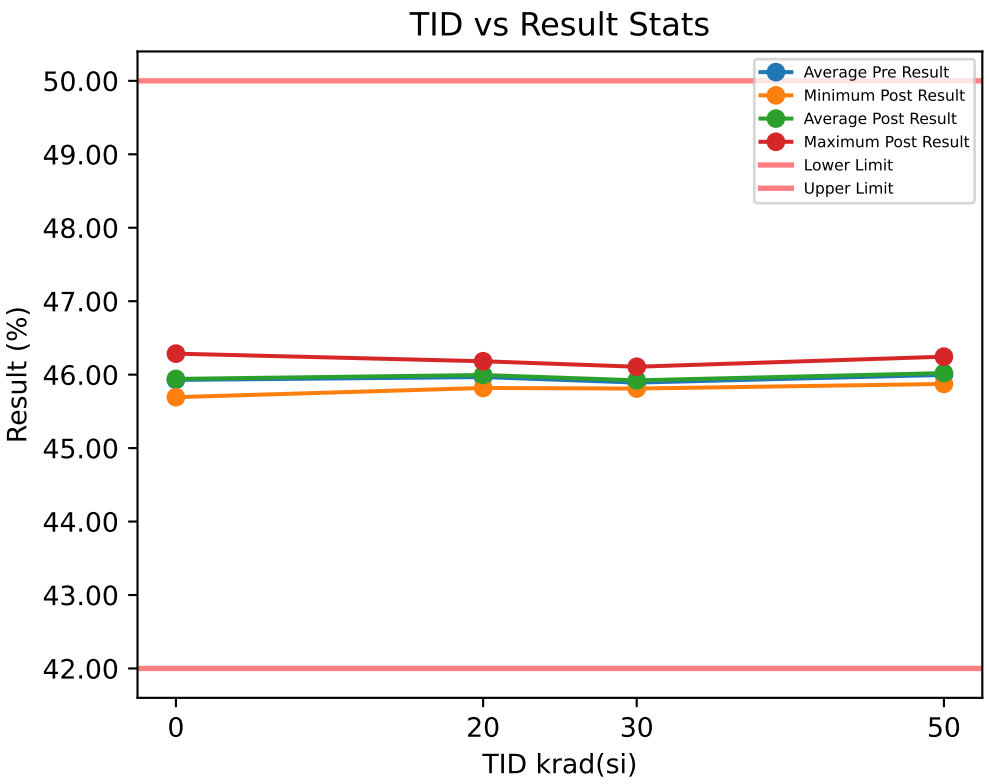
Test Results (Lower Limit = 42.0, Upper Limit = 50.0 (%))

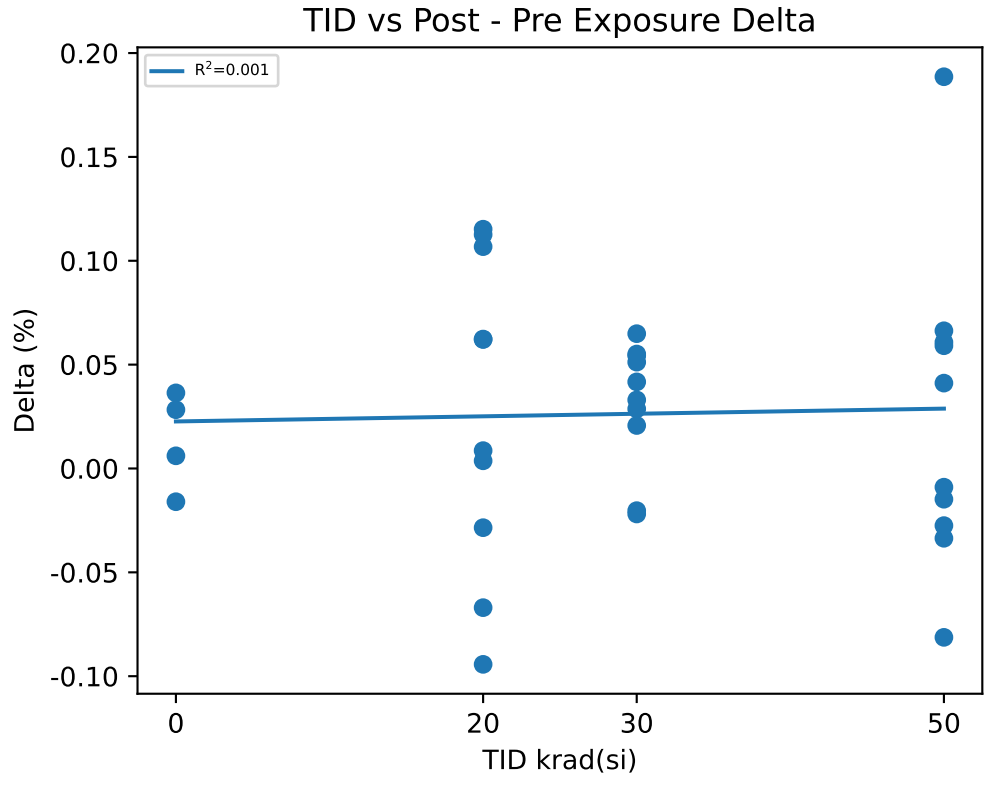
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	45.929	45.901	-0.0282
2	20	Unbiased	46.057	46.142	0.0851
3	50	Biased	45.949	46.13	0.1815
4	30	Unbiased	45.929	45.969	0.0397
5	50	Unbiased	46.18	46.191	0.0111
6	30	Biased	46.075	46.104	0.0288
7	50	Biased	45.976	46.035	0.0596
8	30	Unbiased	45.801	45.867	0.0656
9	20	Unbiased	46.004	45.932	-0.0719
10	50	Biased	45.815	45.864	0.0497
11	30	Biased	45.832	45.855	0.0231
12	0	Correlation	45.84	45.861	0.0203
13	0	Correlation	45.646	45.678	0.0317
14	50	Unbiased	45.989	45.908	-0.0813
15	20	Biased	46.064	46.064	-0.0002
16	20	Unbiased	46.062	46.052	-0.0099
17	20	Biased	46.115	46.167	0.0513
18	20	Unbiased	45.783	45.844	0.0607
19	20	Biased	45.846	45.845	-0.0013
20	50	Unbiased	45.961	45.928	-0.0327
21	0	Correlation	46.288	46.253	-0.035
22	50	Unbiased	46.003	45.977	-0.0257
23	0	Correlation	45.946	45.907	-0.0385
24	20	Biased	45.964	45.914	-0.0505
26	50	Biased	45.974	46.02	0.0456
27	30	Unbiased	45.912	45.931	0.0184
28	30	Biased	45.753	45.811	0.0575
29	30	Unbiased	45.85	45.89	0.0398
30	20	Biased	45.97	46.08	0.1098
31	30	Unbiased	45.844	45.831	-0.0131
33	30	Biased	46.003	46.055	0.0528
34	50	Unbiased	46.181	46.228	0.0478
35	20	Unbiased	45.865	45.941	0.0765
41	30	Biased	45.959	45.933	-0.0261

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	45.646	45.93	46.288	0.2692	45.678	45.925	46.253	0.24046	-0.0385	-0.005375	0.0317	0.036554
20	45.783	45.973	46.115	0.10971	45.844	45.998	46.167	0.11788	-0.0719	0.02496	0.1098	0.060604
30	45.753	45.896	46.075	0.0984	45.811	45.925	46.104	0.09572	-0.0261	0.02865	0.0656	0.029634
50	45.815	45.996	46.181	0.11048	45.864	46.018	46.228	0.12751	-0.0813	0.02274	0.1815	0.072584

Device Test: 27.18 LEVEL|DCL/OUT/5/5/0/0/5/100kHz//@MAX_DCL_50





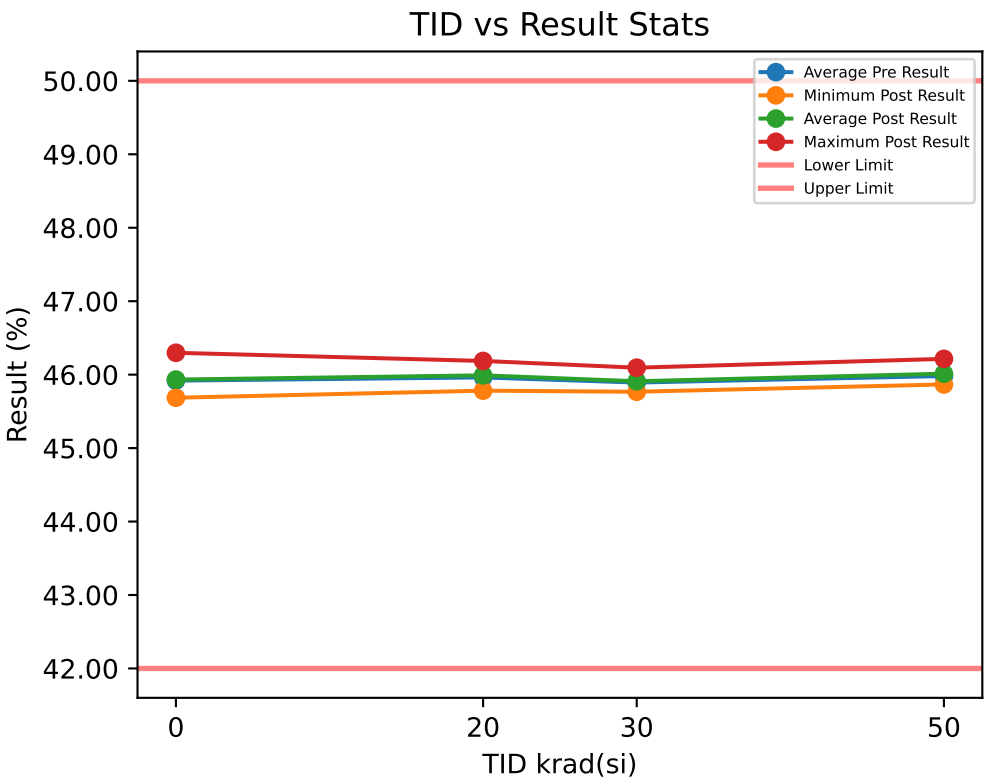
Test Results (Lower Limit = 42.0, Upper Limit = 50.0 (%))

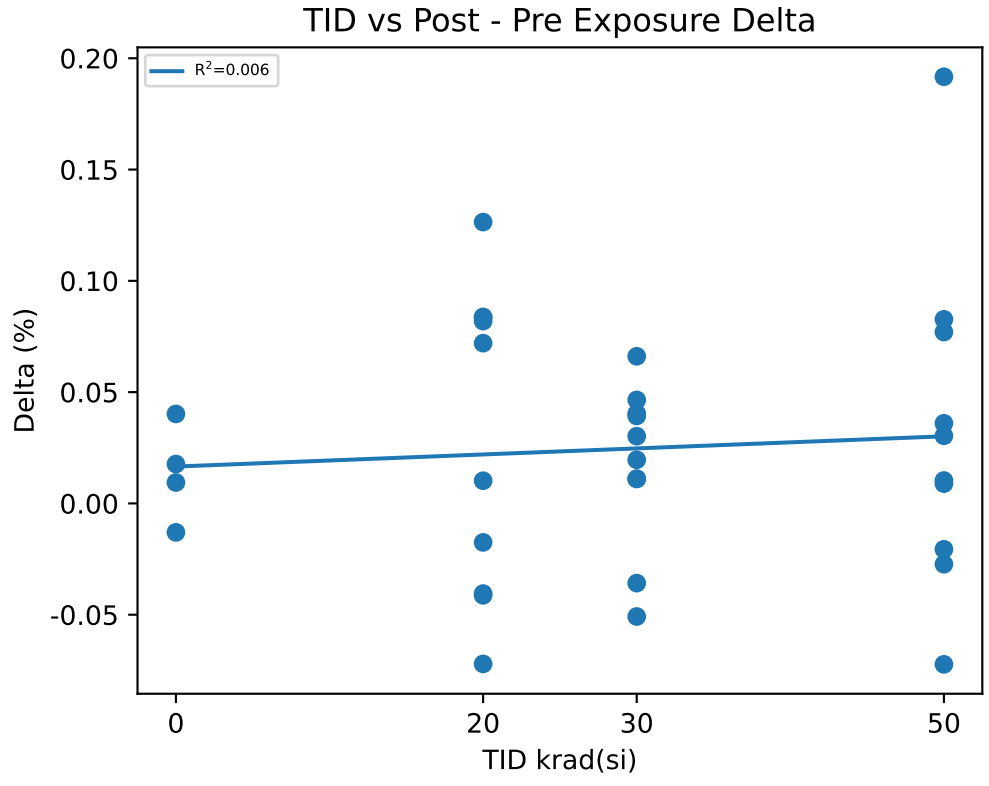
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	45.935	45.907	-0.0275
2	20	Unbiased	46.013	46.126	0.1126
3	50	Biased	45.938	46.127	0.1886
4	30	Unbiased	45.932	45.974	0.0417
5	50	Unbiased	46.197	46.183	-0.0148
6	30	Biased	46.087	46.108	0.0207
7	50	Biased	46.003	46.062	0.0591
8	30	Unbiased	45.803	45.858	0.0551
9	20	Unbiased	46.007	45.912	-0.0943
10	50	Biased	45.807	45.873	0.0663
11	30	Biased	45.819	45.871	0.0512
12	0	Correlation	45.849	45.855	0.0061
13	0	Correlation	45.657	45.693	0.0364
14	50	Unbiased	46.002	45.92	-0.0813
15	20	Biased	46.058	46.067	0.0086
16	20	Unbiased	46.081	46.084	0.0037
17	20	Biased	46.12	46.182	0.0623
18	20	Unbiased	45.758	45.865	0.1068
19	20	Biased	45.847	45.819	-0.0285
20	50	Unbiased	45.956	45.923	-0.0336
21	0	Correlation	46.302	46.286	-0.016
22	50	Unbiased	45.981	45.972	-0.009
23	0	Correlation	45.905	45.933	0.0283
24	20	Biased	45.965	45.898	-0.067
26	50	Biased	45.94	46	0.0608
27	30	Unbiased	45.873	45.927	0.0543
28	30	Biased	45.745	45.81	0.0649
29	30	Unbiased	45.832	45.865	0.033
30	20	Biased	45.944	46.059	0.1152
31	30	Unbiased	45.848	45.826	-0.0219
33	30	Biased	46.022	46.051	0.0287
34	50	Unbiased	46.204	46.245	0.0411
35	20	Unbiased	45.879	45.941	0.0621
41	30	Biased	45.955	45.935	-0.0203

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	45.657	45.928	46.302	0.27091	45.693	45.942	46.286	0.25023	-0.016	0.0137	0.0364	0.023582
20	45.758	45.967	46.12	0.11297	45.819	45.995	46.182	0.12322	-0.0943	0.02815	0.1152	0.075609
30	45.745	45.892	46.087	0.10599	45.81	45.922	46.108	0.097506	-0.0219	0.03074	0.0649	0.030442
50	45.807	45.996	46.204	0.12089	45.873	46.021	46.245	0.12755	-0.0813	0.02497	0.1886	0.075575

Device Test: 27.19 LEVEL|DCL/OUT/12/12/0/0/5/100kHz//@MAX_DCL_50





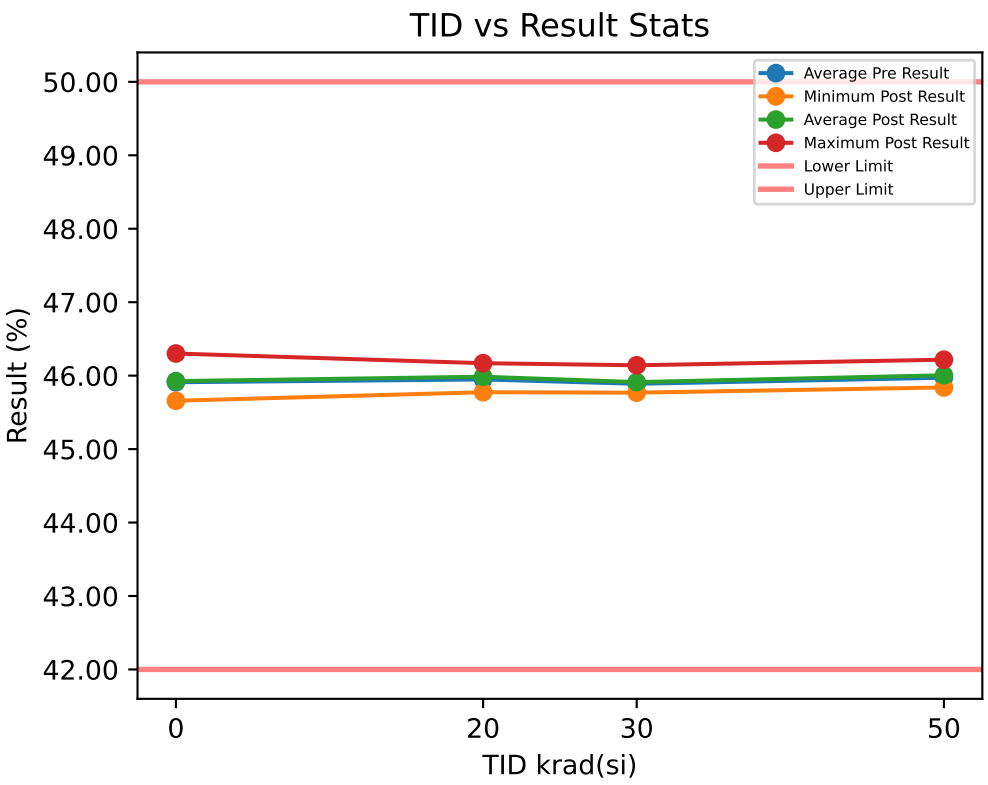
Test Results (Lower Limit = 42.0, Upper Limit = 50.0 (%))

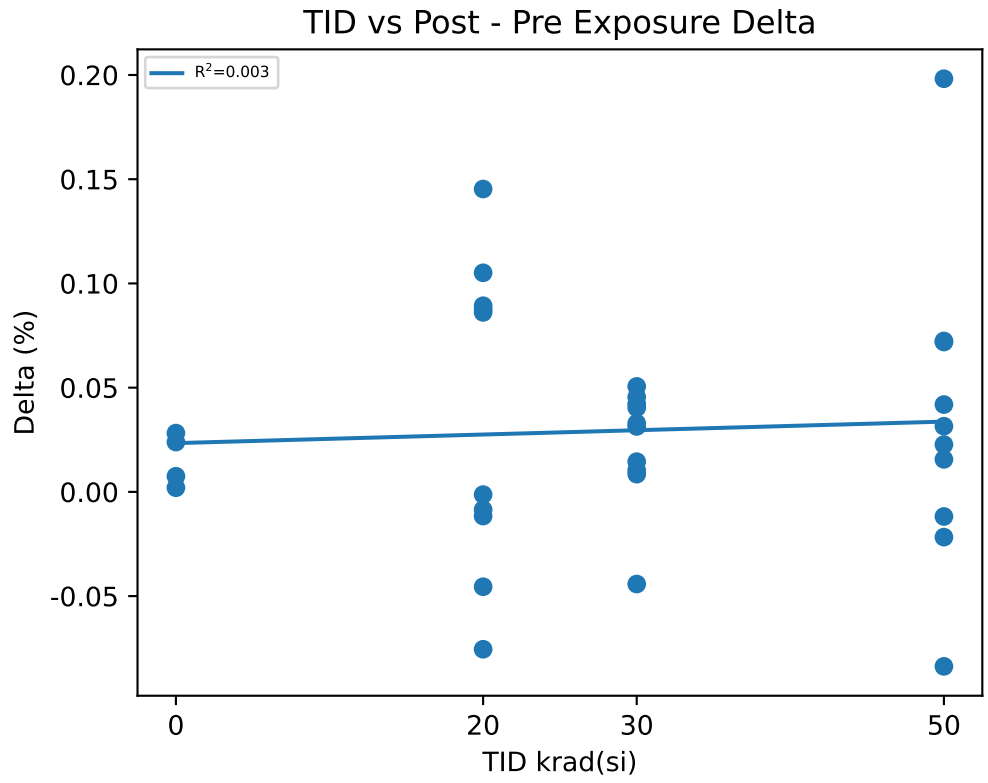
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	45.894	45.867	-0.0273
2	20	Unbiased	46.005	46.087	0.0819
3	50	Biased	45.924	46.115	0.1917
4	30	Unbiased	45.94	45.979	0.0393
5	50	Unbiased	46.15	46.159	0.0089
6	30	Biased	46.13	46.095	-0.0358
7	50	Biased	46.002	46.013	0.0103
8	30	Unbiased	45.806	45.836	0.0302
9	20	Unbiased	45.96	45.919	-0.0413
10	50	Biased	45.786	45.869	0.0827
11	30	Biased	45.807	45.848	0.0404
12	0	Correlation	45.843	45.831	-0.013
13	0	Correlation	45.646	45.686	0.0402
14	50	Unbiased	46.001	45.929	-0.0723
15	20	Biased	46.07	46.03	-0.0405
16	20	Unbiased	46.083	46.093	0.0102
17	20	Biased	46.103	46.187	0.0835
18	20	Unbiased	45.743	45.869	0.1264
19	20	Biased	45.854	45.782	-0.0721
20	50	Unbiased	45.974	45.954	-0.0206
21	0	Correlation	46.288	46.298	0.0094
22	50	Unbiased	45.965	45.996	0.0304
23	0	Correlation	45.899	45.917	0.0177
24	20	Biased	45.966	45.949	-0.0175
26	50	Biased	45.937	46.014	0.077
27	30	Unbiased	45.879	45.946	0.0661
28	30	Biased	45.756	45.767	0.0111
29	30	Unbiased	45.834	45.845	0.011
30	20	Biased	45.981	46.053	0.072
31	30	Unbiased	45.861	45.81	-0.0508
33	30	Biased	45.972	46.018	0.0465
34	50	Unbiased	46.179	46.215	0.036
35	20	Unbiased	45.854	45.938	0.0838
41	30	Biased	45.937	45.956	0.0196

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	45.646	45.919	46.288	0.26908	45.686	45.933	46.298	0.26133	-0.013	0.013575	0.0402	0.021982
20	45.743	45.962	46.103	0.11542	45.782	45.991	46.187	0.12098	-0.0721	0.02864	0.1264	0.068812
30	45.756	45.892	46.13	0.10803	45.767	45.91	46.095	0.10429	-0.0508	0.01776	0.0661	0.036449
50	45.786	45.981	46.179	0.11533	45.867	46.013	46.215	0.11816	-0.0723	0.03168	0.1917	0.073245

Device Test: 27.20 LEVEL|DCL/OUT/14/14/0/0/5/100kHz//@MAX_DCL_50





Test Results (Lower Limit = 42.0, Upper Limit = 50.0 (%))

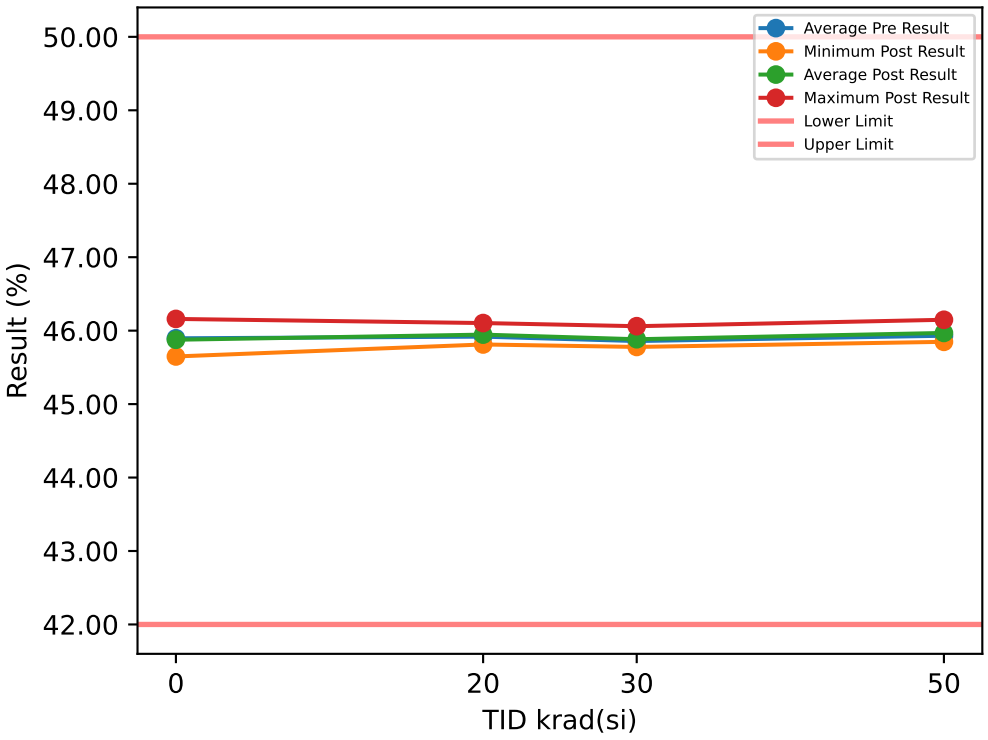
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	45.889	45.877	-0.0118
2	20	Unbiased	45.989	46.077	0.0874
3	50	Biased	45.901	46.099	0.1982
4	30	Unbiased	45.943	45.986	0.0422
5	50	Unbiased	46.127	46.15	0.0227
6	30	Biased	46.11	46.141	0.0314
7	50	Biased	46.008	46.023	0.0156
8	30	Unbiased	45.79	45.841	0.0506
9	20	Unbiased	45.982	45.936	-0.0455
10	50	Biased	45.767	45.839	0.0719
11	30	Biased	45.82	45.861	0.0404
12	0	Correlation	45.856	45.858	0.002
13	0	Correlation	45.634	45.658	0.0239
14	50	Unbiased	46.004	45.92	-0.0837
15	20	Biased	46.022	46.02	-0.0013
16	20	Unbiased	46.098	46.089	-0.0085
17	20	Biased	46.083	46.169	0.0861
18	20	Unbiased	45.738	45.883	0.1453
19	20	Biased	45.85	45.775	-0.0755
20	50	Unbiased	45.971	45.949	-0.0217
21	0	Correlation	46.273	46.301	0.0282
22	50	Unbiased	45.947	45.989	0.0419
23	0	Correlation	45.877	45.884	0.0075
24	20	Biased	45.968	45.956	-0.0116
26	50	Biased	45.917	45.99	0.0724
27	30	Unbiased	45.905	45.938	0.0329
28	30	Biased	45.76	45.768	0.0085
29	30	Unbiased	45.799	45.813	0.0145
30	20	Biased	45.915	46.02	0.1051
31	30	Unbiased	45.861	45.817	-0.0442
33	30	Biased	45.963	46.009	0.0455
34	50	Unbiased	46.186	46.217	0.0315
35	20	Unbiased	45.84	45.929	0.0893
41	30	Biased	45.936	45.947	0.0104

Test Statistics (%)

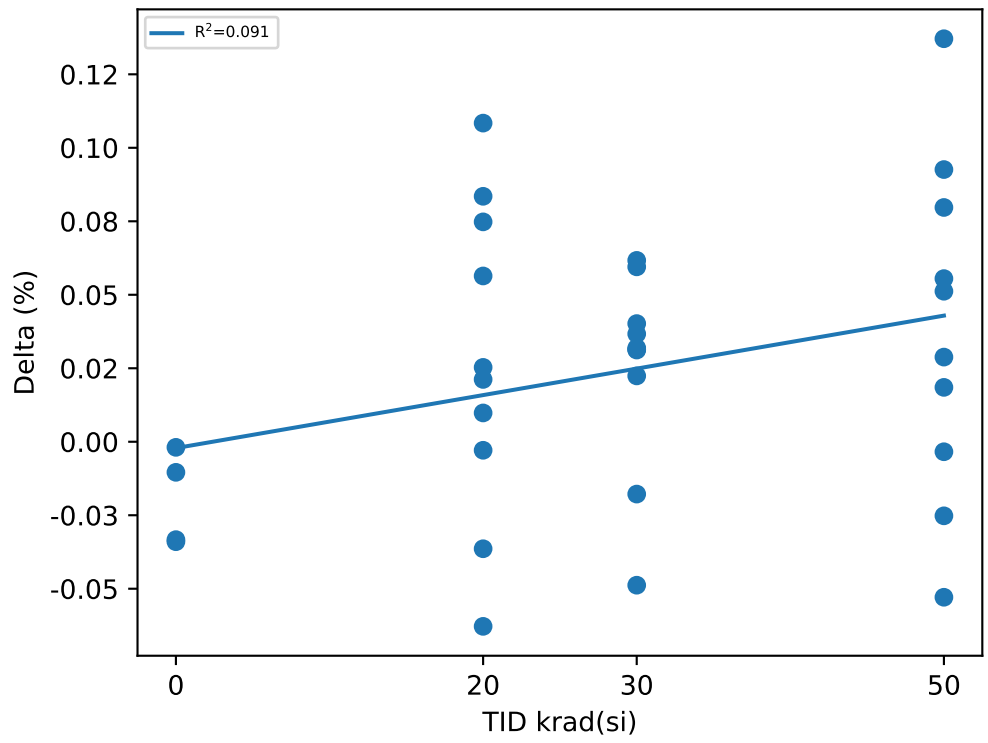
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	45.634	45.91	46.273	0.26573	45.658	45.925	46.301	0.27012	0.002	0.0154	0.0282	0.012624
20	45.738	45.948	46.098	0.11351	45.775	45.986	46.169	0.11393	-0.0755	0.03708	0.1453	0.074098
30	45.76	45.889	46.11	0.10529	45.768	45.912	46.141	0.11365	-0.0442	0.02322	0.0506	0.028017
50	45.767	45.972	46.186	0.11995	45.839	46.005	46.217	0.1202	-0.0837	0.0337	0.1982	0.074132

Device Test: 27.21 LEVEL|DCL/OUT/4.5/4.5/0/0/4.5/200kHz//@MAX_DCL_50

TID vs Result Stats



TID vs Post - Pre Exposure Delta



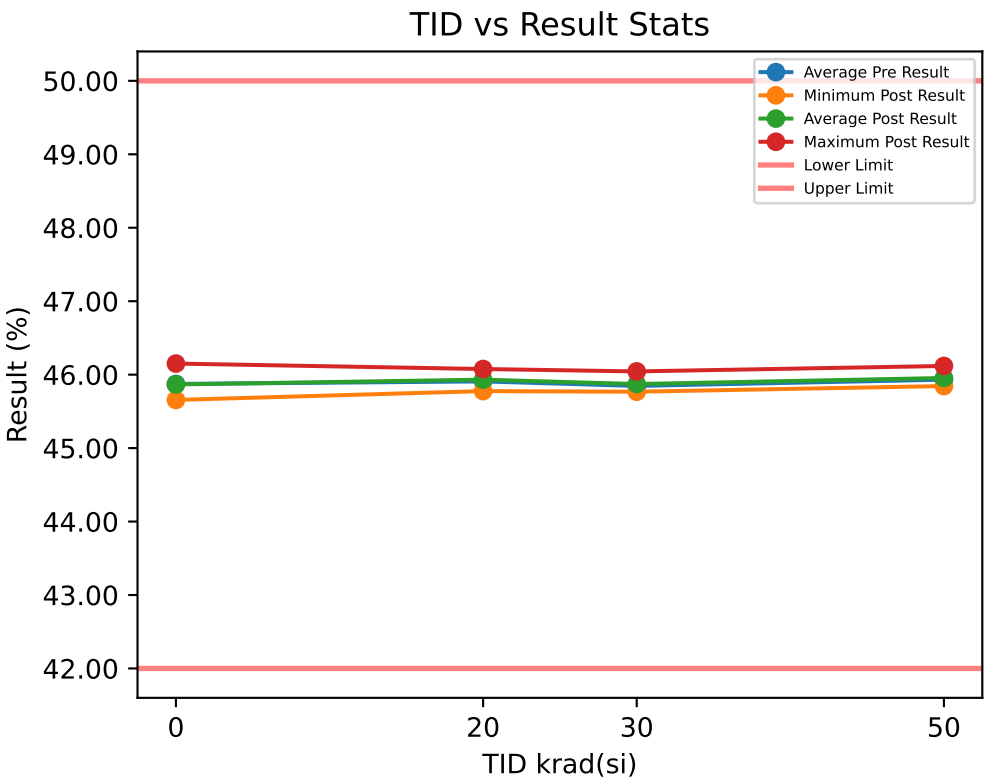
Test Results (Lower Limit = 42.0, Upper Limit = 50.0 (%))

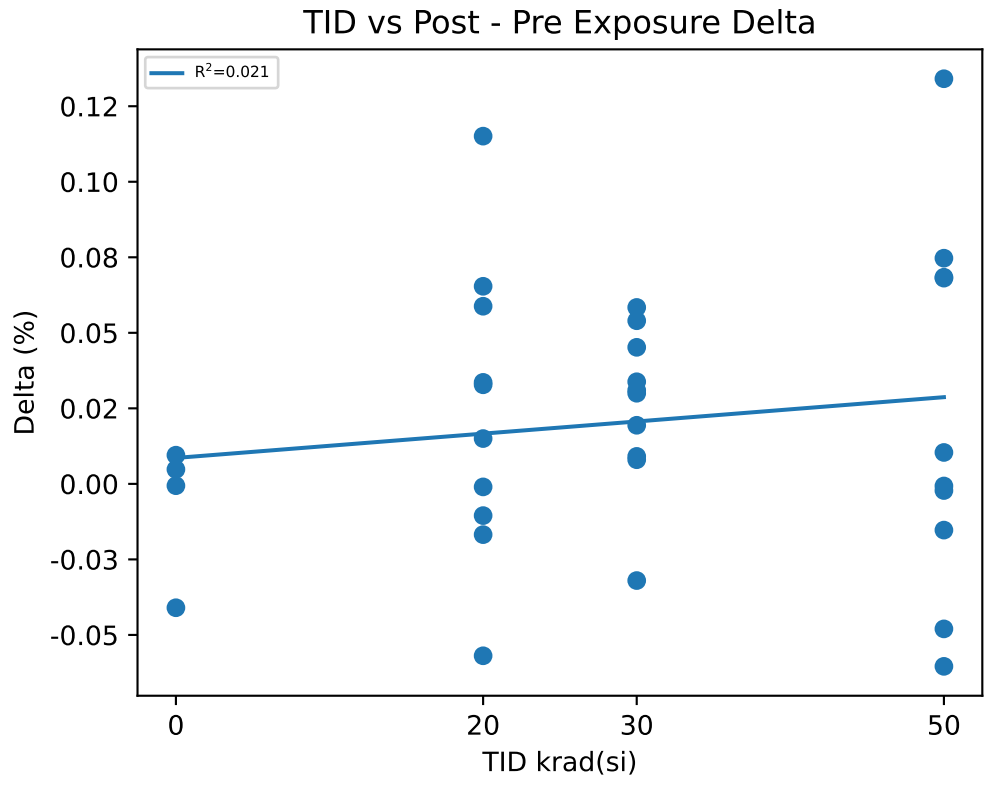
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	45.916	45.912	-0.0034
2	20	Unbiased	45.995	46.103	0.1084
3	50	Biased	45.882	46.019	0.1371
4	30	Unbiased	45.909	45.946	0.0367
5	50	Unbiased	46.066	46.095	0.0288
6	30	Biased	46.001	46.061	0.0595
7	50	Biased	45.938	46.031	0.0926
8	30	Unbiased	45.8	45.832	0.0319
9	20	Unbiased	45.966	45.903	-0.0628
10	50	Biased	45.768	45.848	0.0797
11	30	Biased	45.789	45.821	0.0314
12	0	Correlation	45.85	45.848	-0.0019
13	0	Correlation	45.659	45.648	-0.0104
14	50	Unbiased	45.896	45.87	-0.0252
15	20	Biased	45.993	46.014	0.0212
16	20	Unbiased	45.999	45.996	-0.0029
17	20	Biased	46.04	46.066	0.0253
18	20	Unbiased	45.755	45.812	0.0564
19	20	Biased	45.802	45.812	0.0098
20	50	Unbiased	45.929	45.876	-0.0529
21	0	Correlation	46.193	46.16	-0.0333
22	50	Unbiased	45.893	45.912	0.0185
23	0	Correlation	45.882	45.848	-0.034
24	20	Biased	45.899	45.862	-0.0364
26	50	Biased	45.923	45.978	0.0555
27	30	Unbiased	45.861	45.892	0.0312
28	30	Biased	45.749	45.811	0.0617
29	30	Unbiased	45.783	45.824	0.0402
30	20	Biased	45.91	45.994	0.0835
31	30	Unbiased	45.827	45.778	-0.0488
33	30	Biased	45.951	45.974	0.0224
34	50	Unbiased	46.097	46.148	0.0512
35	20	Unbiased	45.822	45.897	0.0748
41	30	Biased	45.911	45.893	-0.0178

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	45.659	45.896	46.193	0.22109	45.648	45.876	46.16	0.21111	-0.034	-0.0199	-0.0019	0.016254
20	45.755	45.918	46.04	0.097136	45.812	45.946	46.103	0.10314	-0.0628	0.02773	0.1084	0.054029
30	45.749	45.858	46.001	0.082374	45.778	45.883	46.061	0.088273	-0.0488	0.02484	0.0617	0.033857
50	45.768	45.931	46.097	0.092897	45.848	45.969	46.148	0.10207	-0.0529	0.03819	0.1371	0.05721

Device Test: 27.22 LEVEL|DCL/OUT/5/5/0/0/5/200kHz//@MAX_DCL_50





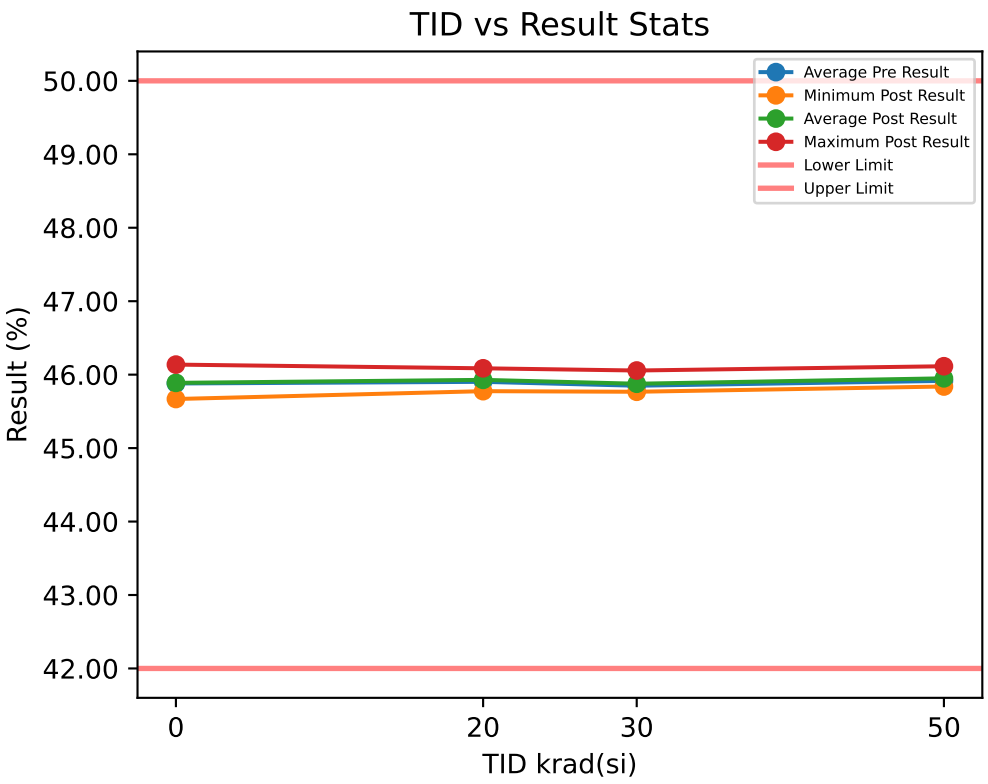
Test Results (Lower Limit = 42.0, Upper Limit = 50.0 (%))

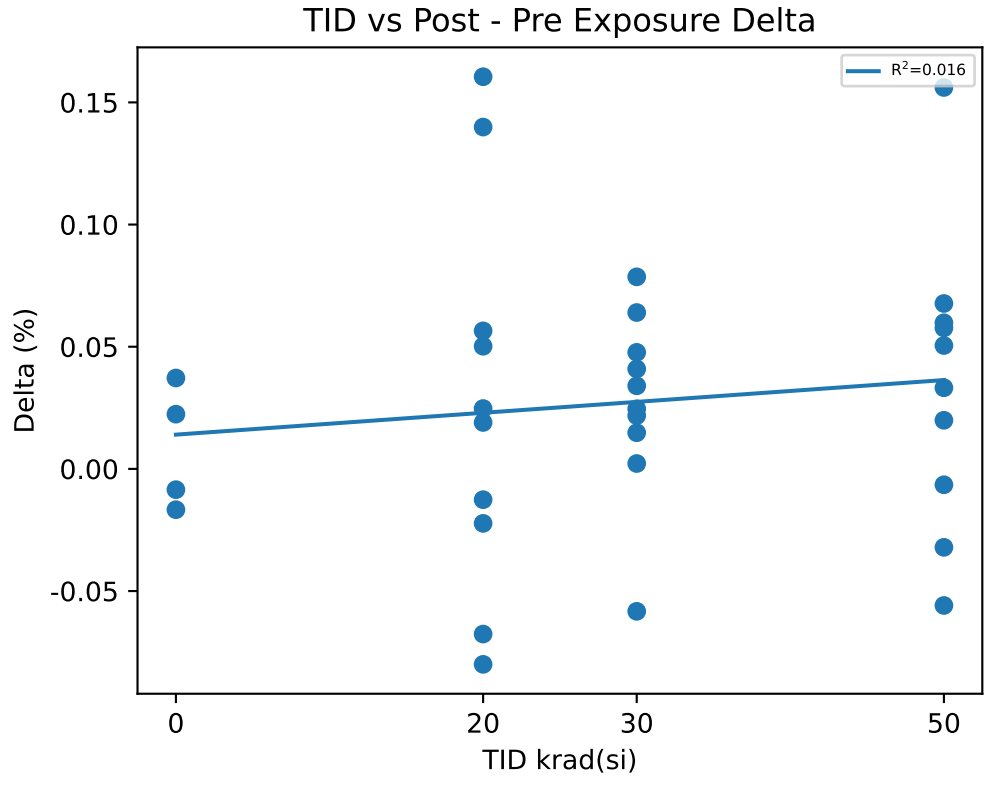
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	45.891	45.876	-0.0153
2	20	Unbiased	45.962	46.077	0.1151
3	50	Biased	45.878	46.012	0.1341
4	30	Unbiased	45.909	45.928	0.0194
5	50	Unbiased	46.081	46.08	-0.0007
6	30	Biased	46.036	46.044	0.008
7	50	Biased	45.935	46.01	0.0747
8	30	Unbiased	45.801	45.846	0.0452
9	20	Unbiased	45.95	45.893	-0.0569
10	50	Biased	45.776	45.845	0.0684
11	30	Biased	45.762	45.796	0.0338
12	0	Correlation	45.827	45.831	0.0048
13	0	Correlation	45.646	45.656	0.0095
14	50	Unbiased	45.907	45.859	-0.048
15	20	Biased	45.986	46.001	0.015
16	20	Unbiased	45.983	45.973	-0.0105
17	20	Biased	46.033	46.066	0.0328
18	20	Unbiased	45.742	45.776	0.0336
19	20	Biased	45.787	45.786	-0.001
20	50	Unbiased	45.928	45.868	-0.0604
21	0	Correlation	46.151	46.151	-0.0006
22	50	Unbiased	45.895	45.906	0.0104
23	0	Correlation	45.869	45.828	-0.041
24	20	Biased	45.894	45.877	-0.0168
26	50	Biased	45.903	45.971	0.0681
27	30	Unbiased	45.847	45.878	0.031
28	30	Biased	45.728	45.786	0.0584
29	30	Unbiased	45.768	45.822	0.054
30	20	Biased	45.921	45.98	0.0588
31	30	Unbiased	45.8	45.768	-0.032
33	30	Biased	45.924	45.954	0.03
34	50	Unbiased	46.12	46.118	-0.0022
35	20	Unbiased	45.824	45.889	0.0654
41	30	Biased	45.891	45.9	0.0091

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	45.646	45.873	46.151	0.20902	45.656	45.867	46.151	0.20649	-0.041	-0.006825	0.0095	0.023154
20	45.742	45.908	46.033	0.095278	45.776	45.932	46.077	0.10531	-0.0569	0.02355	0.1151	0.048873
30	45.728	45.847	46.036	0.093821	45.768	45.872	46.044	0.086494	-0.032	0.02569	0.0584	0.0265
50	45.776	45.932	46.12	0.099552	45.845	45.954	46.118	0.098018	-0.0604	0.02291	0.1341	0.0614

Device Test: 27.23 LEVEL|DCL/OUT/12/12/0/0/5/200kHz//@MAX_DCL_50





Test Results (Lower Limit = 42.0, Upper Limit = 50.0 (%))

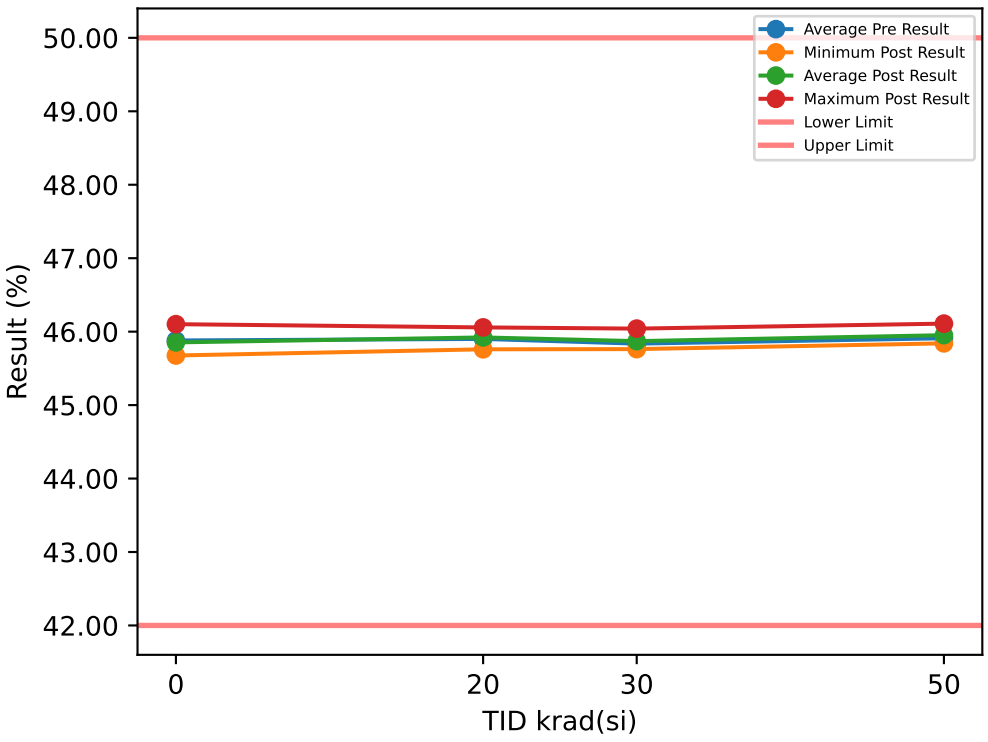
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	45.882	45.875	-0.0065
2	20	Unbiased	45.926	46.086	0.1605
3	50	Biased	45.877	46.033	0.1561
4	30	Unbiased	45.888	45.929	0.0409
5	50	Unbiased	46.066	46.099	0.0332
6	30	Biased	45.978	46.056	0.0786
7	50	Biased	45.935	45.986	0.0505
8	30	Unbiased	45.79	45.814	0.0246
9	20	Unbiased	45.961	45.894	-0.0676
10	50	Biased	45.771	45.839	0.0677
11	30	Biased	45.8	45.822	0.0218
12	0	Correlation	45.845	45.882	0.0372
13	0	Correlation	45.646	45.668	0.0224
14	50	Unbiased	45.88	45.848	-0.0321
15	20	Biased	45.992	46.017	0.0247
16	20	Unbiased	45.977	45.965	-0.0126
17	20	Biased	46.034	46.053	0.019
18	20	Unbiased	45.725	45.775	0.0502
19	20	Biased	45.81	45.788	-0.0223
20	50	Unbiased	45.927	45.871	-0.0559
21	0	Correlation	46.145	46.137	-0.0085
22	50	Unbiased	45.881	45.901	0.0199
23	0	Correlation	45.883	45.866	-0.0167
24	20	Biased	45.886	45.806	-0.08
26	50	Biased	45.876	45.936	0.0598
27	30	Unbiased	45.872	45.886	0.0148
28	30	Biased	45.73	45.794	0.064
29	30	Unbiased	45.779	45.827	0.0477
30	20	Biased	45.879	46.019	0.1399
31	30	Unbiased	45.825	45.767	-0.0583
33	30	Biased	45.938	45.971	0.034
34	50	Unbiased	46.057	46.114	0.0577
35	20	Unbiased	45.83	45.887	0.0565
41	30	Biased	45.892	45.894	0.0022

Test Statistics (%)

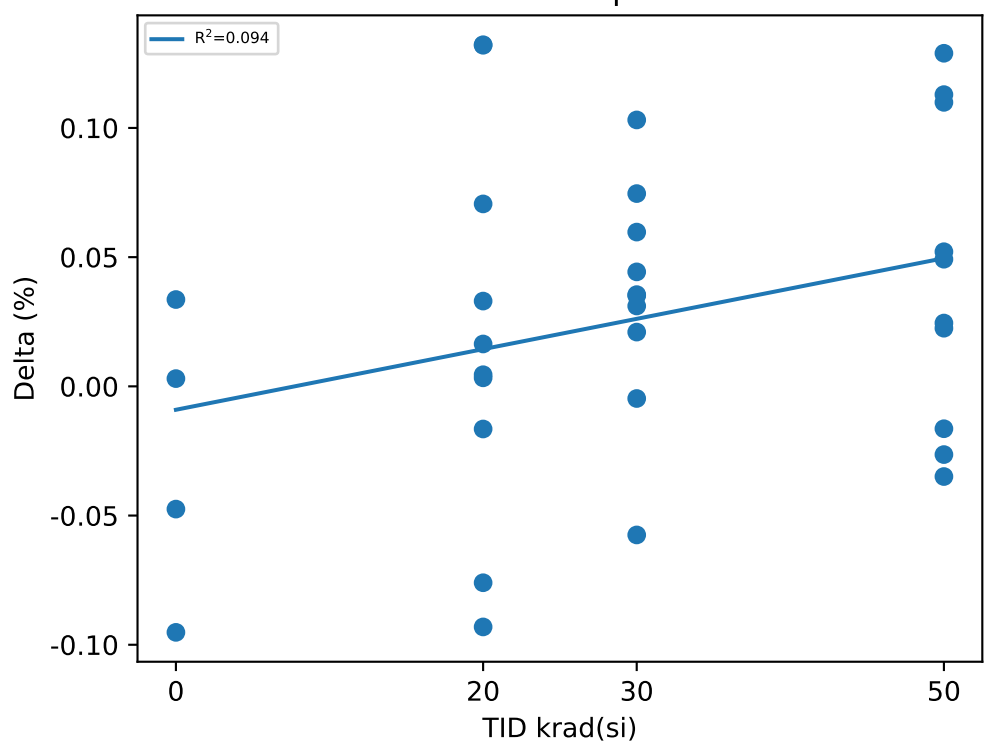
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	45.646	45.88	46.145	0.20525	45.668	45.888	46.137	0.19204	-0.0167	0.0086	0.0372	0.025436
20	45.725	45.902	46.034	0.094938	45.775	45.929	46.086	0.11504	-0.08	0.02683	0.1605	0.079192
30	45.73	45.849	45.978	0.077202	45.767	45.876	46.056	0.089767	-0.0583	0.02703	0.0786	0.037676
50	45.771	45.915	46.066	0.088633	45.839	45.95	46.114	0.10262	-0.0559	0.03504	0.1561	0.059464

Device Test: 27.24 LEVEL|DCL/OUT/14/14/0/0/5/200kHz//@MAX_DCL_50

TID vs Result Stats



TID vs Post - Pre Exposure Delta



Test Results (Lower Limit = 42.0, Upper Limit = 50.0 (%))

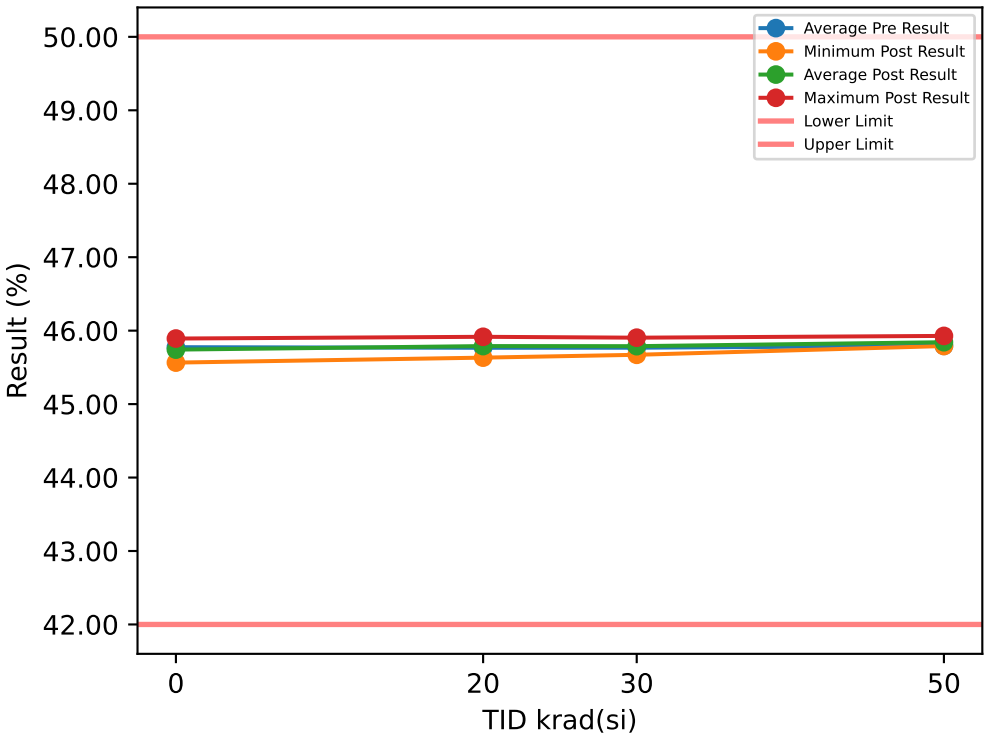
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	45.885	45.868	-0.0164
2	20	Unbiased	45.926	46.058	0.132
3	50	Biased	45.885	46.014	0.1289
4	30	Unbiased	45.877	45.921	0.0443
5	50	Unbiased	46.043	46.095	0.0521
6	30	Biased	45.967	46.041	0.0746
7	50	Biased	45.926	45.975	0.0492
8	30	Unbiased	45.781	45.812	0.0311
9	20	Unbiased	45.957	45.881	-0.076
10	50	Biased	45.765	45.875	0.1099
11	30	Biased	45.789	45.848	0.0597
12	0	Correlation	45.835	45.838	0.003
13	0	Correlation	45.642	45.675	0.0336
14	50	Unbiased	45.876	45.841	-0.0349
15	20	Biased	46.016	46.032	0.0164
16	20	Unbiased	45.974	45.958	-0.0165
17	20	Biased	46.028	46.031	0.0033
18	20	Unbiased	45.727	45.76	0.033
19	20	Biased	45.783	45.787	0.0045
20	50	Unbiased	45.905	45.879	-0.0264
21	0	Correlation	46.149	46.102	-0.0475
22	50	Unbiased	45.87	45.894	0.0245
23	0	Correlation	45.894	45.799	-0.0952
24	20	Biased	45.885	45.792	-0.0931
26	50	Biased	45.858	45.971	0.1129
27	30	Unbiased	45.855	45.876	0.021
28	30	Biased	45.72	45.823	0.1031
29	30	Unbiased	45.754	45.789	0.0351
30	20	Biased	45.886	46.018	0.1322
31	30	Unbiased	45.82	45.762	-0.0575
33	30	Biased	45.913	45.949	0.0355
34	50	Unbiased	46.087	46.109	0.0225
35	20	Unbiased	45.827	45.898	0.0706
41	30	Biased	45.891	45.886	-0.0047

Test Statistics (%)

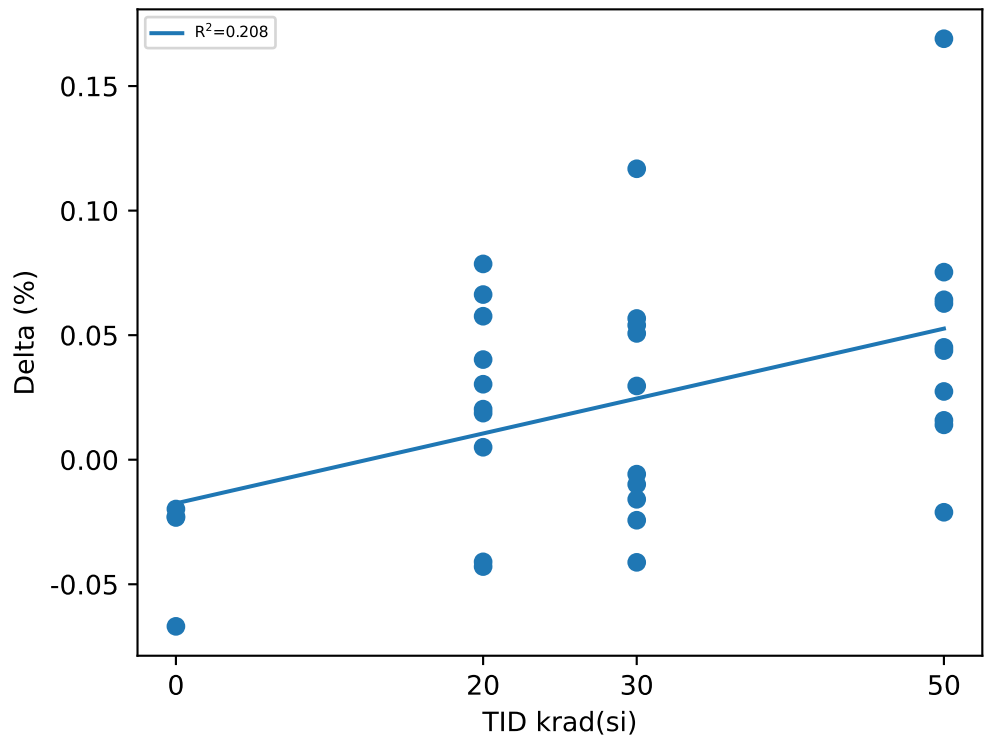
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	45.642	45.88	46.149	0.20933	45.675	45.854	46.102	0.17942	-0.0952	-0.026525	0.0336	0.056695
20	45.727	45.901	46.028	0.099218	45.76	45.921	46.058	0.11386	-0.0931	0.02064	0.1322	0.075814
30	45.72	45.837	45.967	0.077322	45.762	45.871	46.041	0.083408	-0.0575	0.03422	0.1031	0.043767
50	45.765	45.91	46.087	0.092371	45.841	45.952	46.109	0.096486	-0.0349	0.04223	0.1289	0.059658

Device Test: 27.25 LEVEL|DCL/OUT/4.5/4.5/0/0/4.5/500kHz//@MAX_DCL_50

TID vs Result Stats



TID vs Post - Pre Exposure Delta



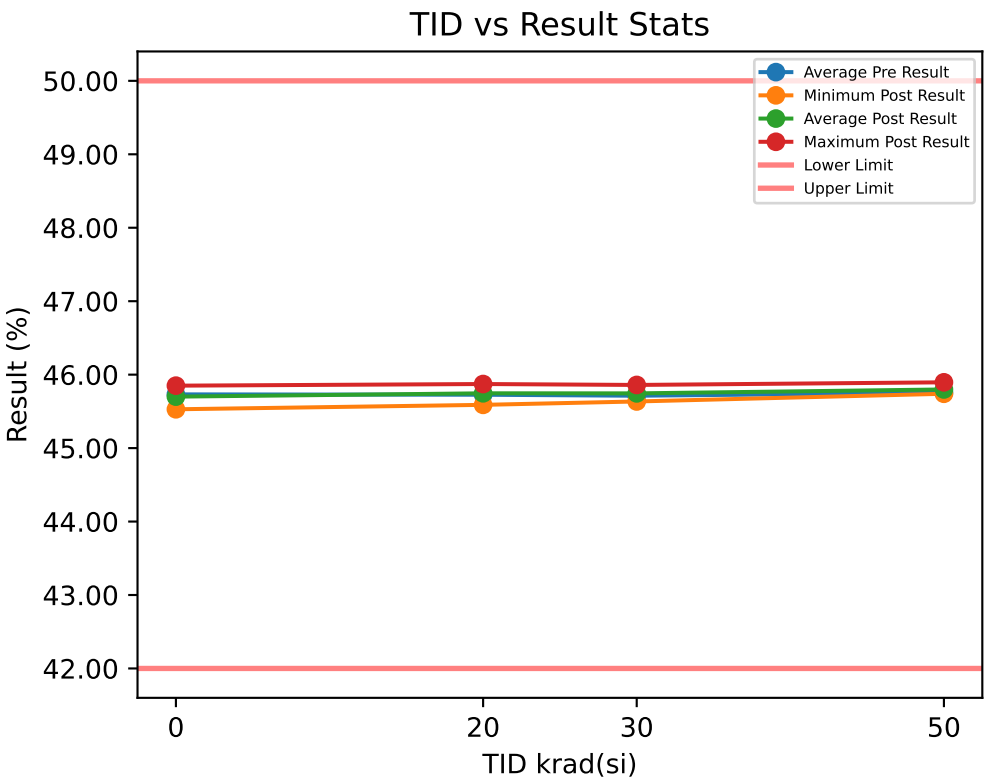
Test Results (Lower Limit = 42.0, Upper Limit = 50.0 (%))

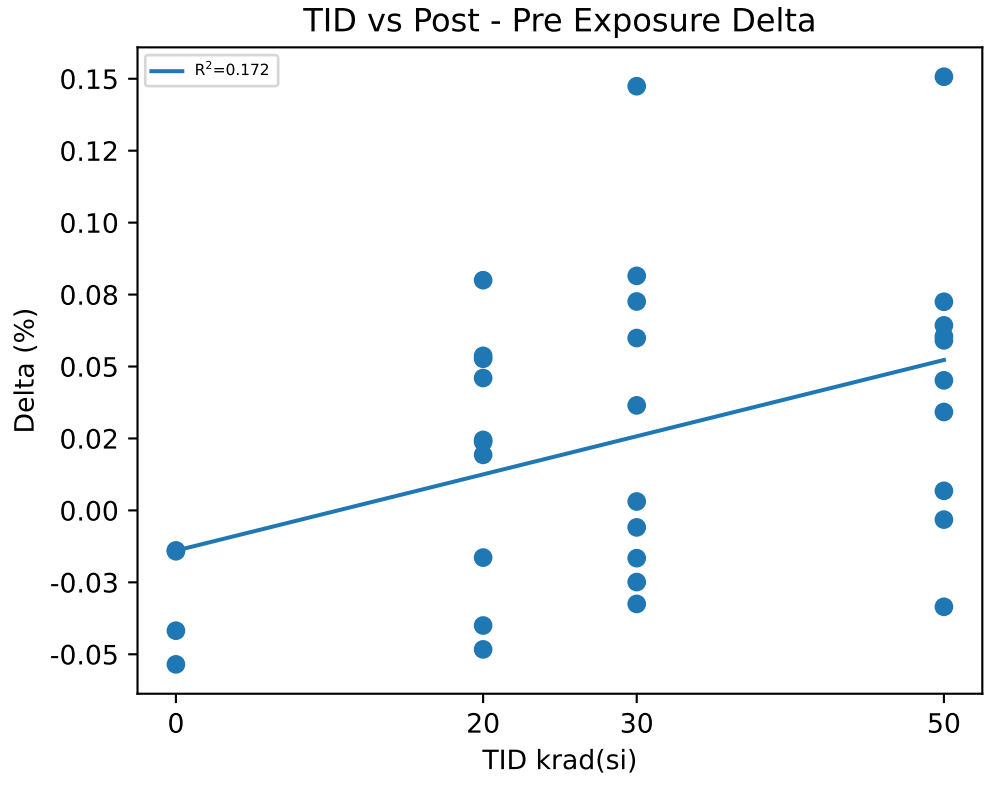
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	45.834	45.85	0.0158
2	20	Unbiased	45.85	45.916	0.0663
3	50	Biased	45.807	45.852	0.0451
4	30	Unbiased	45.864	45.855	-0.0099
5	50	Unbiased	45.816	45.878	0.0627
6	30	Biased	45.853	45.904	0.0507
7	50	Biased	45.828	45.842	0.014
8	30	Unbiased	45.763	45.747	-0.0159
9	20	Unbiased	45.784	45.802	0.0187
10	50	Biased	45.626	45.795	0.169
11	30	Biased	45.723	45.78	0.0567
12	0	Correlation	45.791	45.771	-0.0198
13	0	Correlation	45.588	45.565	-0.0228
14	50	Unbiased	45.8	45.844	0.0438
15	20	Biased	45.838	45.878	0.0402
16	20	Unbiased	45.876	45.835	-0.041
17	20	Biased	45.792	45.797	0.005
18	20	Unbiased	45.612	45.633	0.0203
19	20	Biased	45.654	45.684	0.0303
20	50	Unbiased	45.842	45.82	-0.0211
21	0	Correlation	45.916	45.892	-0.0232
22	50	Unbiased	45.715	45.791	0.0753
23	0	Correlation	45.806	45.739	-0.0669
24	20	Biased	45.797	45.755	-0.0429
26	50	Biased	45.761	45.825	0.0642
27	30	Unbiased	45.778	45.808	0.0296
28	30	Biased	45.696	45.671	-0.0243
29	30	Unbiased	45.718	45.712	-0.0058
30	20	Biased	45.722	45.801	0.0786
31	30	Unbiased	45.73	45.689	-0.0412
33	30	Biased	45.831	45.885	0.054
34	50	Unbiased	45.901	45.928	0.0274
35	20	Unbiased	45.742	45.8	0.0576
41	30	Biased	45.719	45.836	0.1168

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	45.588	45.775	45.916	0.13664	45.565	45.742	45.892	0.13517	-0.0669	-0.033175	-0.0198	0.022534
20	45.612	45.767	45.876	0.084962	45.633	45.79	45.916	0.083925	-0.0429	0.02331	0.0786	0.041231
30	45.696	45.768	45.864	0.061771	45.671	45.789	45.904	0.082306	-0.0412	0.02107	0.1168	0.048822
50	45.626	45.793	45.901	0.076509	45.791	45.843	45.928	0.040216	-0.0211	0.04962	0.169	0.050834

Device Test: 27.26 LEVEL|DCL/OUT/5/5/0/0/5/500kHz//@MAX_DCL_50





Test Results (Lower Limit = 42.0, Upper Limit = 50.0 (%))

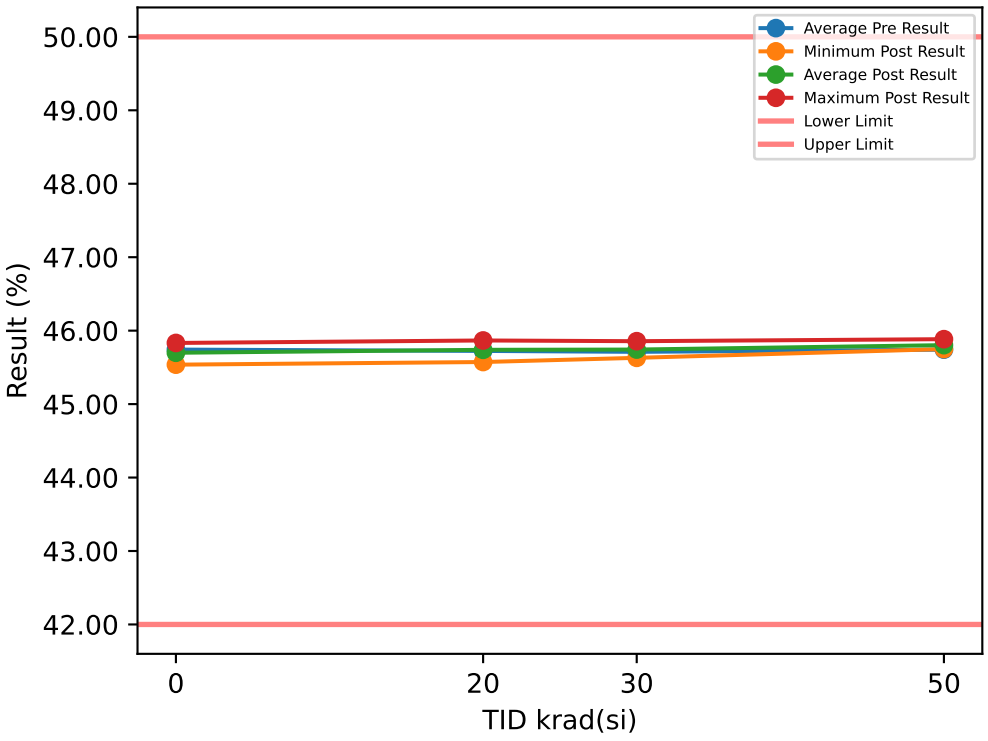
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	45.788	45.785	-0.0032
2	20	Unbiased	45.826	45.872	0.046
3	50	Biased	45.72	45.784	0.0643
4	30	Unbiased	45.814	45.817	0.0031
5	50	Unbiased	45.776	45.836	0.0605
6	30	Biased	45.787	45.86	0.0726
7	50	Biased	45.782	45.827	0.0452
8	30	Unbiased	45.703	45.687	-0.0166
9	20	Unbiased	45.713	45.766	0.0527
10	50	Biased	45.589	45.74	0.1507
11	30	Biased	45.664	45.745	0.0815
12	0	Correlation	45.735	45.721	-0.0139
13	0	Correlation	45.543	45.528	-0.0142
14	50	Unbiased	45.773	45.78	0.0068
15	20	Biased	45.801	45.826	0.0245
16	20	Unbiased	45.844	45.795	-0.0483
17	20	Biased	45.746	45.77	0.0238
18	20	Unbiased	45.569	45.589	0.0193
19	20	Biased	45.628	45.612	-0.0164
20	50	Unbiased	45.806	45.773	-0.0335
21	0	Correlation	45.892	45.85	-0.0418
22	50	Unbiased	45.687	45.76	0.0725
23	0	Correlation	45.757	45.704	-0.0535
24	20	Biased	45.752	45.712	-0.04
26	50	Biased	45.746	45.805	0.0591
27	30	Unbiased	45.712	45.772	0.0599
28	30	Biased	45.66	45.635	-0.0249
29	30	Unbiased	45.664	45.658	-0.0059
30	20	Biased	45.679	45.759	0.08
31	30	Unbiased	45.677	45.645	-0.0325
33	30	Biased	45.79	45.827	0.0365
34	50	Unbiased	45.861	45.896	0.0342
35	20	Unbiased	45.705	45.759	0.0537
41	30	Biased	45.658	45.806	0.1474

Test Statistics (%)

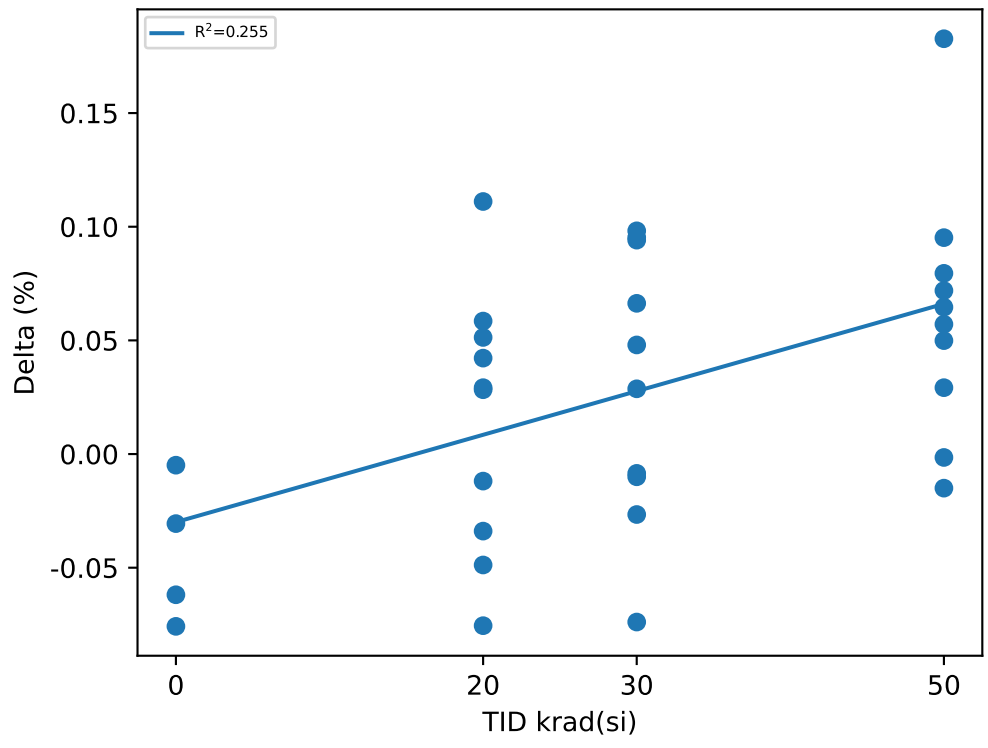
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	45.543	45.732	45.892	0.14381	45.528	45.701	45.85	0.13214	-0.0535	-0.03085	-0.0139	0.019979
20	45.569	45.726	45.844	0.08659	45.589	45.746	45.872	0.088102	-0.0483	0.01953	0.08	0.0423
30	45.658	45.713	45.814	0.061135	45.635	45.745	45.86	0.083382	-0.0325	0.03211	0.1474	0.057971
50	45.589	45.753	45.861	0.074498	45.74	45.798	45.896	0.044789	-0.0335	0.04566	0.1507	0.050329

Device Test: 27.27 LEVEL|DCL/OUT/12/12/0/0/5/500kHz//@MAX_DCL_50

TID vs Result Stats



TID vs Post - Pre Exposure Delta



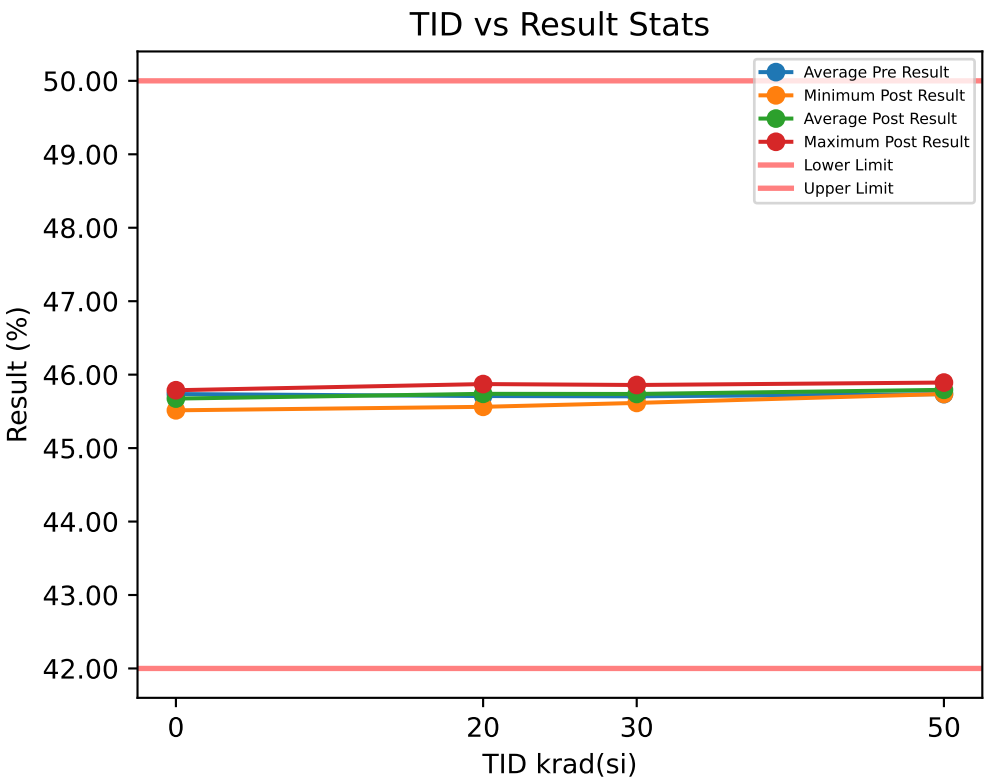
Test Results (Lower Limit = 42.0, Upper Limit = 50.0 (%))

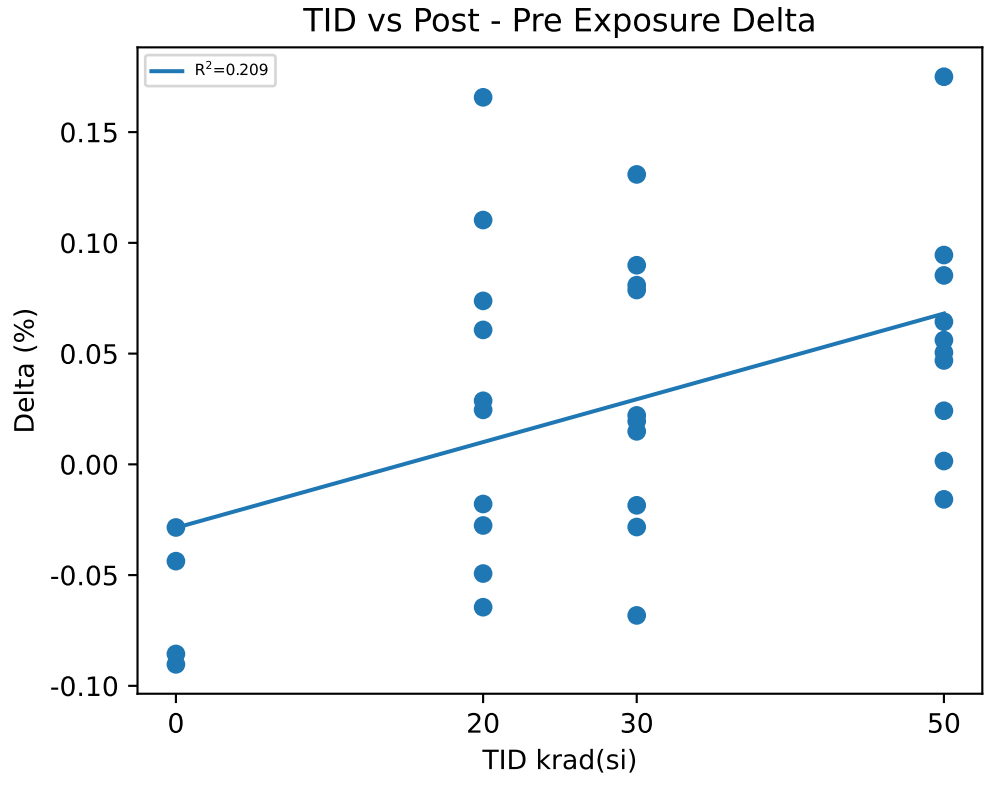
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	45.784	45.769	-0.015
2	20	Unbiased	45.808	45.866	0.0585
3	50	Biased	45.737	45.802	0.0646
4	30	Unbiased	45.807	45.798	-0.0085
5	50	Unbiased	45.781	45.861	0.0795
6	30	Biased	45.788	45.854	0.0663
7	50	Biased	45.794	45.823	0.0292
8	30	Unbiased	45.694	45.668	-0.0266
9	20	Unbiased	45.721	45.749	0.0283
10	50	Biased	45.586	45.769	0.1827
11	30	Biased	45.662	45.758	0.0953
12	0	Correlation	45.741	45.736	-0.0049
13	0	Correlation	45.568	45.537	-0.0306
14	50	Unbiased	45.741	45.798	0.0571
15	20	Biased	45.812	45.855	0.0422
16	20	Unbiased	45.827	45.778	-0.0488
17	20	Biased	45.769	45.735	-0.0339
18	20	Unbiased	45.544	45.573	0.0292
19	20	Biased	45.633	45.621	-0.0119
20	50	Unbiased	45.789	45.788	-0.0015
21	0	Correlation	45.908	45.832	-0.0758
22	50	Unbiased	45.654	45.749	0.0952
23	0	Correlation	45.752	45.69	-0.0619
24	20	Biased	45.778	45.703	-0.0755
26	50	Biased	45.711	45.783	0.0719
27	30	Unbiased	45.731	45.759	0.0287
28	30	Biased	45.64	45.63	-0.01
29	30	Unbiased	45.641	45.689	0.048
30	20	Biased	45.639	45.751	0.1111
31	30	Unbiased	45.705	45.631	-0.0739
33	30	Biased	45.762	45.856	0.0941
34	50	Unbiased	45.834	45.884	0.0499
35	20	Unbiased	45.708	45.76	0.0513
41	30	Biased	45.685	45.783	0.0982

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	45.568	45.742	45.908	0.13924	45.537	45.699	45.832	0.12324	-0.0758	-0.0433	-0.0049	0.031823
20	45.544	45.724	45.827	0.093396	45.573	45.739	45.866	0.09105	-0.0755	0.01505	0.1111	0.056705
30	45.64	45.711	45.807	0.059142	45.63	45.743	45.856	0.084553	-0.0739	0.03116	0.0982	0.059381
50	45.586	45.741	45.834	0.074393	45.749	45.803	45.884	0.042353	-0.015	0.06136	0.1827	0.055061

Device Test: 27.28 LEVEL|DCL/OUT/14/14/0/0/5/500kHz//@MAX_DCL_50





Test Results (Lower Limit = 42.0, Upper Limit = 50.0 (%))

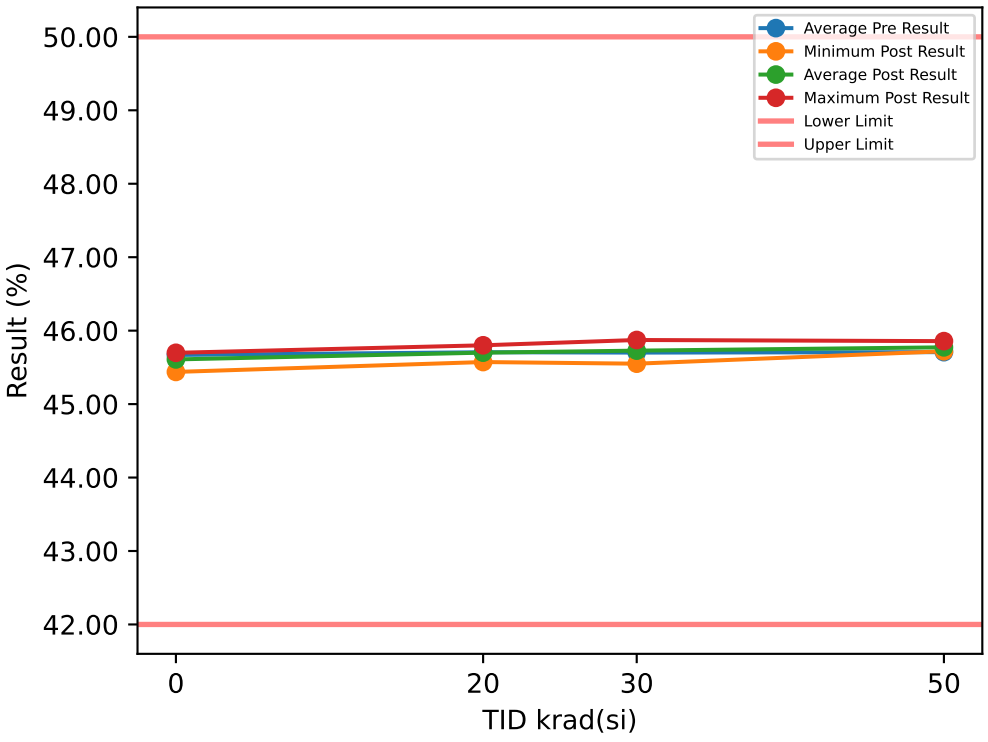
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	45.765	45.767	0.0015
2	20	Unbiased	45.761	45.872	0.1103
3	50	Biased	45.762	45.809	0.0469
4	30	Unbiased	45.786	45.806	0.0195
5	50	Unbiased	45.793	45.849	0.0561
6	30	Biased	45.765	45.846	0.0809
7	50	Biased	45.786	45.81	0.0242
8	30	Unbiased	45.69	45.662	-0.0283
9	20	Unbiased	45.713	45.738	0.0246
10	50	Biased	45.574	45.749	0.175
11	30	Biased	45.662	45.752	0.0899
12	0	Correlation	45.764	45.736	-0.0285
13	0	Correlation	45.558	45.514	-0.0437
14	50	Unbiased	45.736	45.787	0.0505
15	20	Biased	45.808	45.869	0.0607
16	20	Unbiased	45.815	45.765	-0.0493
17	20	Biased	45.752	45.734	-0.0179
18	20	Unbiased	45.533	45.562	0.0287
19	20	Biased	45.66	45.633	-0.0276
20	50	Unbiased	45.79	45.774	-0.0158
21	0	Correlation	45.873	45.788	-0.0856
22	50	Unbiased	45.642	45.737	0.0945
23	0	Correlation	45.748	45.658	-0.0903
24	20	Biased	45.733	45.669	-0.0645
26	50	Biased	45.674	45.759	0.0853
27	30	Unbiased	45.732	45.754	0.0221
28	30	Biased	45.641	45.623	-0.0185
29	30	Unbiased	45.65	45.665	0.0149
30	20	Biased	45.617	45.783	0.1657
31	30	Unbiased	45.683	45.615	-0.0682
33	30	Biased	45.781	45.859	0.0787
34	50	Unbiased	45.828	45.892	0.0644
35	20	Unbiased	45.691	45.765	0.0738
41	30	Biased	45.658	45.789	0.1309

Test Statistics (%)

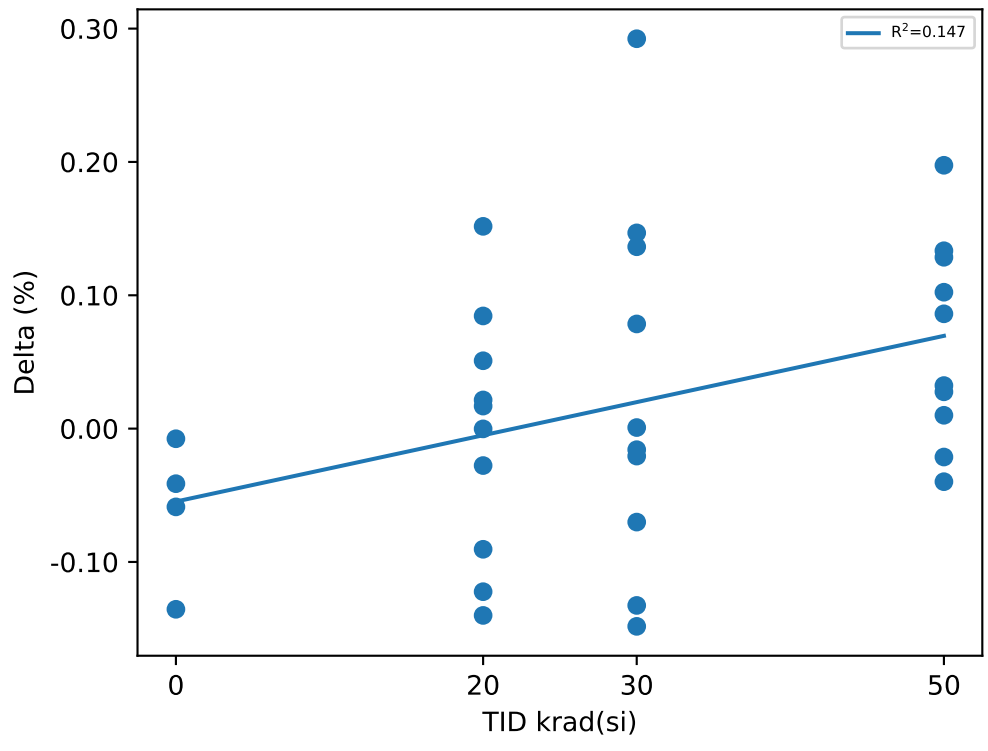
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	45.558	45.736	45.873	0.13105	45.514	45.674	45.788	0.1191	-0.0903	-0.062025	-0.0285	0.030632
20	45.533	45.708	45.815	0.087042	45.562	45.739	45.872	0.0974	-0.0645	0.03045	0.1657	0.073472
30	45.641	45.705	45.786	0.056345	45.615	45.737	45.859	0.090392	-0.0682	0.03219	0.1309	0.061895
50	45.574	45.735	45.828	0.08001	45.737	45.793	45.892	0.048262	-0.0158	0.05826	0.175	0.053511

Device Test: 27.29 LEVEL|DCL/OUT/4.5/4.5/0/0/4.5/1MHz//@MAX_DCL_50

TID vs Result Stats



TID vs Post - Pre Exposure Delta



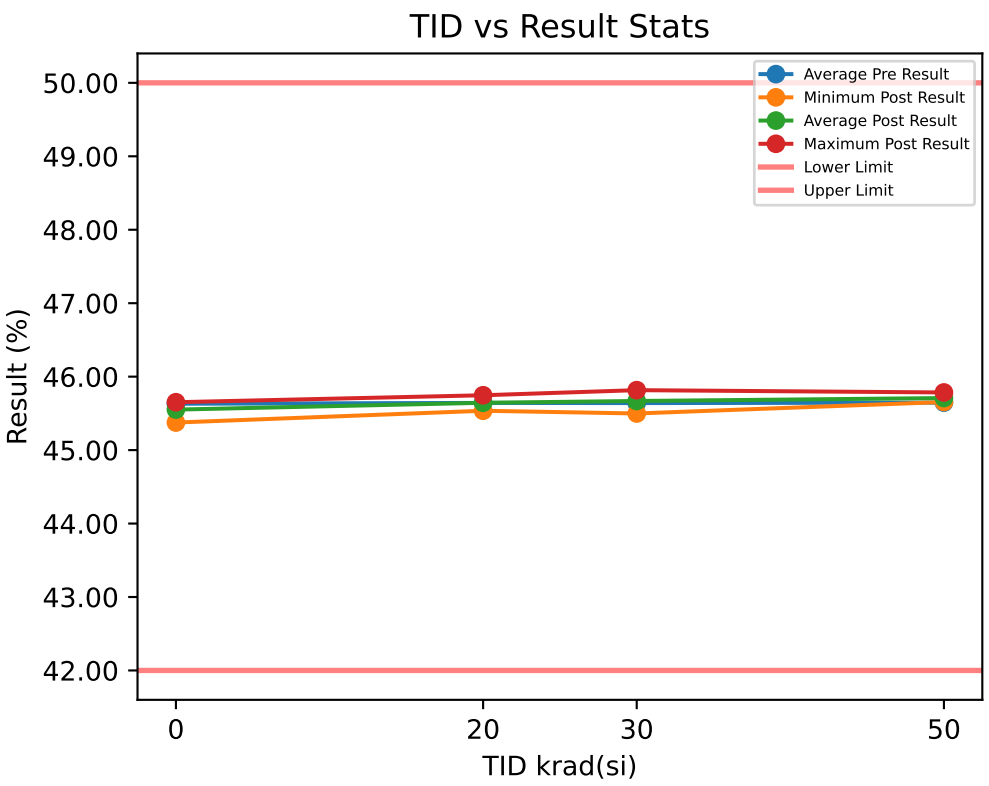
Test Results (Lower Limit = 42.0, Upper Limit = 50.0 (%))

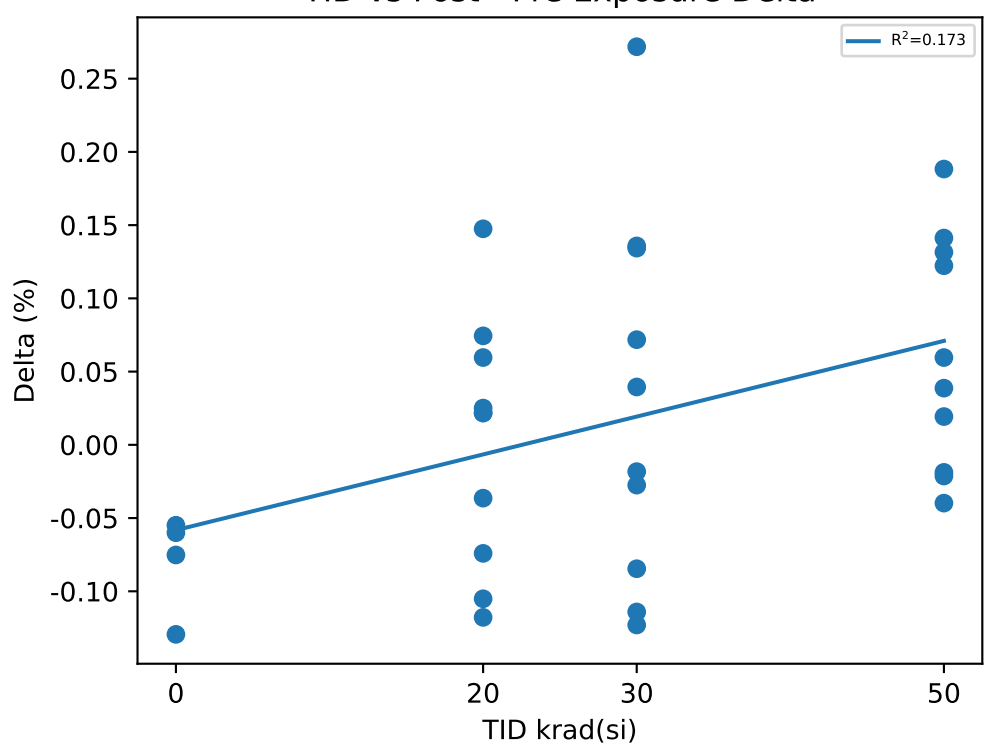
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	45.757	45.785	0.0276
2	20	Unbiased	45.726	45.747	0.0215
3	50	Biased	45.742	45.721	-0.0213
4	30	Unbiased	45.828	45.812	-0.0158
5	50	Unbiased	45.724	45.857	0.1334
6	30	Biased	45.723	45.869	0.1468
7	50	Biased	45.767	45.727	-0.0398
8	30	Unbiased	45.741	45.593	-0.1483
9	20	Unbiased	45.704	45.788	0.0845
10	50	Biased	45.592	45.789	0.1975
11	30	Biased	45.679	45.757	0.0785
12	0	Correlation	45.706	45.698	-0.0076
13	0	Correlation	45.497	45.438	-0.0587
14	50	Unbiased	45.687	45.789	0.1023
15	20	Biased	45.801	45.8	-0.0002
16	20	Unbiased	45.788	45.648	-0.1401
17	20	Biased	45.699	45.671	-0.0277
18	20	Unbiased	45.556	45.573	0.0169
19	20	Biased	45.695	45.605	-0.0905
20	50	Unbiased	45.765	45.775	0.01
21	0	Correlation	45.733	45.692	-0.0413
22	50	Unbiased	45.656	45.785	0.1285
23	0	Correlation	45.74	45.604	-0.1355
24	20	Biased	45.744	45.622	-0.1223
26	50	Biased	45.633	45.719	0.0861
27	30	Unbiased	45.756	45.757	0.0008
28	30	Biased	45.699	45.628	-0.0701
29	30	Unbiased	45.658	45.638	-0.0206
30	20	Biased	45.623	45.775	0.1517
31	30	Unbiased	45.683	45.55	-0.1326
33	30	Biased	45.736	45.873	0.1364
34	50	Unbiased	45.749	45.781	0.0323
35	20	Unbiased	45.725	45.776	0.0509
41	30	Biased	45.509	45.801	0.2924

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	45.497	45.669	45.74	0.11575	45.438	45.608	45.698	0.12125	-0.1355	-0.060775	-0.0076	0.054145
20	45.556	45.706	45.801	0.072702	45.573	45.7	45.8	0.0859	-0.1401	-0.00553	0.1517	0.092333
30	45.509	45.701	45.828	0.083054	45.55	45.728	45.873	0.11688	-0.1483	0.02675	0.2924	0.13737
50	45.592	45.707	45.767	0.061786	45.719	45.773	45.857	0.041782	-0.0398	0.06566	0.1975	0.076028

Device Test: 27.30 LEVEL|DCL/OUT/5/5/0/0/5/1MHz//@MAX_DCL_50





Test Results (Lower Limit = 42.0, Upper Limit = 50.0 (%))

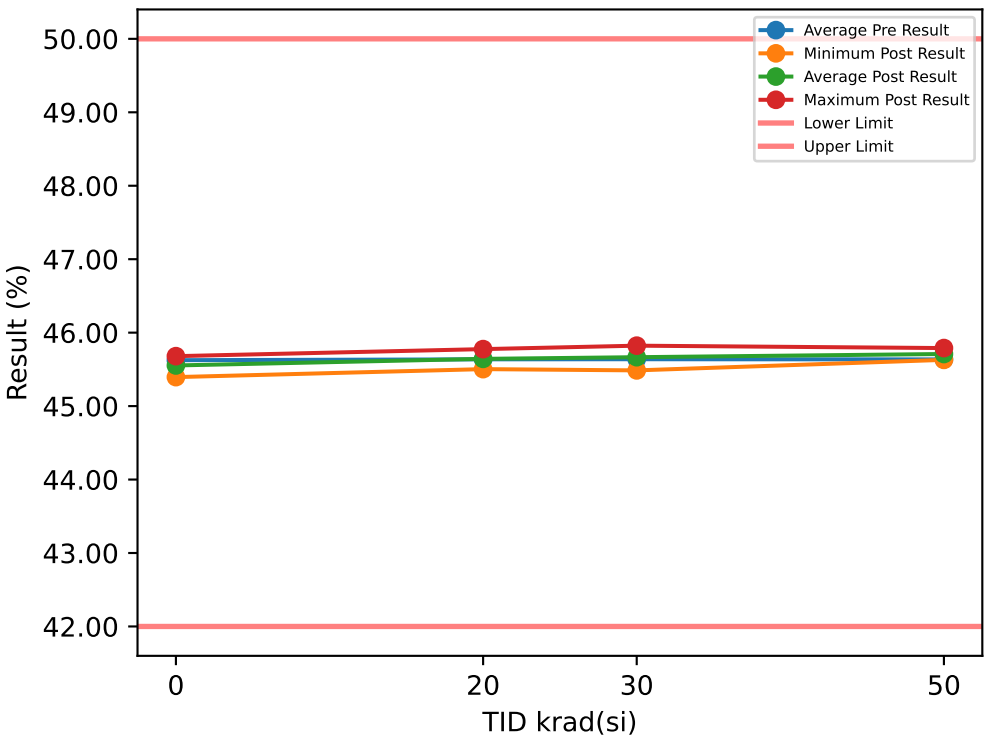
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	45.678	45.697	0.0193
2	20	Unbiased	45.671	45.693	0.0218
3	50	Biased	45.676	45.655	-0.0213
4	30	Unbiased	45.773	45.755	-0.0183
5	50	Unbiased	45.653	45.785	0.1315
6	30	Biased	45.68	45.816	0.1358
7	50	Biased	45.699	45.659	-0.0398
8	30	Unbiased	45.66	45.545	-0.1141
9	20	Unbiased	45.637	45.711	0.0744
10	50	Biased	45.558	45.746	0.1883
11	30	Biased	45.613	45.685	0.0718
12	0	Correlation	45.707	45.652	-0.0549
13	0	Correlation	45.45	45.375	-0.0752
14	50	Unbiased	45.618	45.741	0.1223
15	20	Biased	45.725	45.747	0.0217
16	20	Unbiased	45.715	45.61	-0.1051
17	20	Biased	45.632	45.596	-0.0364
18	20	Unbiased	45.511	45.536	0.0251
19	20	Biased	45.622	45.548	-0.0741
20	50	Unbiased	45.714	45.695	-0.0188
21	0	Correlation	45.684	45.624	-0.06
22	50	Unbiased	45.585	45.727	0.1412
23	0	Correlation	45.683	45.554	-0.1294
24	20	Biased	45.696	45.578	-0.1178
26	50	Biased	45.597	45.657	0.0596
27	30	Unbiased	45.679	45.718	0.0395
28	30	Biased	45.642	45.557	-0.0846
29	30	Unbiased	45.597	45.57	-0.0275
30	20	Biased	45.571	45.719	0.1475
31	30	Unbiased	45.621	45.498	-0.123
33	30	Biased	45.665	45.799	0.1343
34	50	Unbiased	45.683	45.722	0.0387
35	20	Unbiased	45.645	45.704	0.0596
41	30	Biased	45.471	45.743	0.2718

Test Statistics (%)

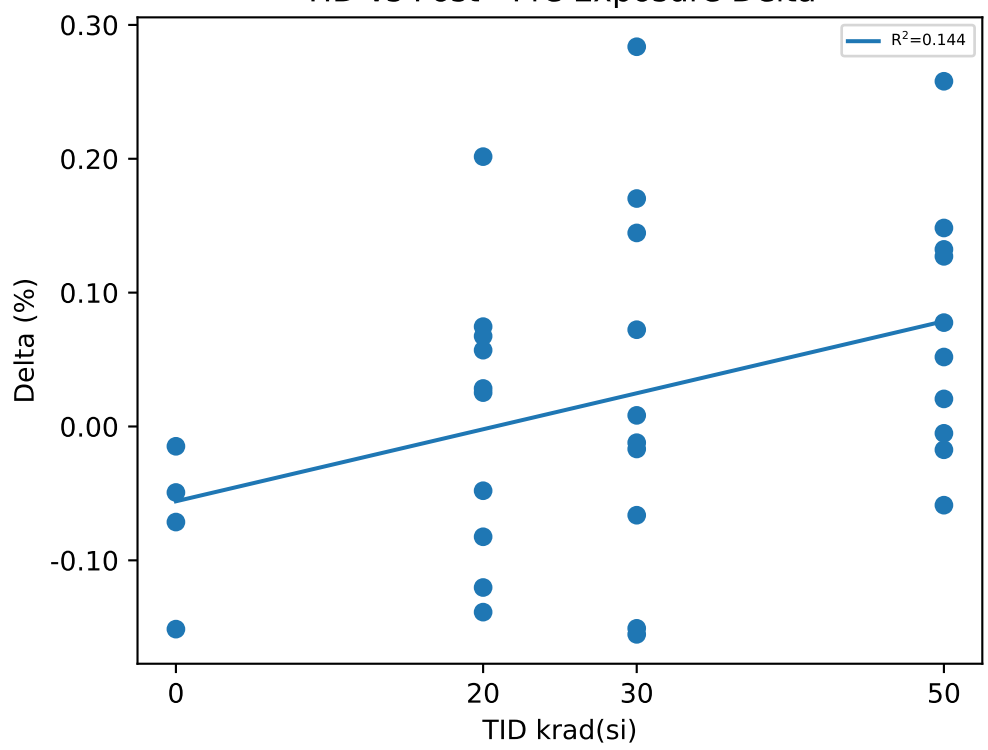
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	45.45	45.631	45.707	0.12099	45.375	45.551	45.652	0.12438	-0.1294	-0.079875	-0.0549	0.034124
20	45.511	45.642	45.725	0.065685	45.536	45.644	45.747	0.078462	-0.1178	0.00167	0.1475	0.084413
30	45.471	45.64	45.773	0.076821	45.498	45.669	45.816	0.11585	-0.123	0.02857	0.2718	0.12706
50	45.558	45.646	45.714	0.053086	45.655	45.708	45.785	0.043621	-0.0398	0.0621	0.1883	0.079508

Device Test: 27.31 LEVEL|DCL/OUT/12/12/0/0/5/1MHz//@MAX_DCL_50

TID vs Result Stats



TID vs Post - Pre Exposure Delta



Test Results (Lower Limit = 42.0, Upper Limit = 50.0 (%))

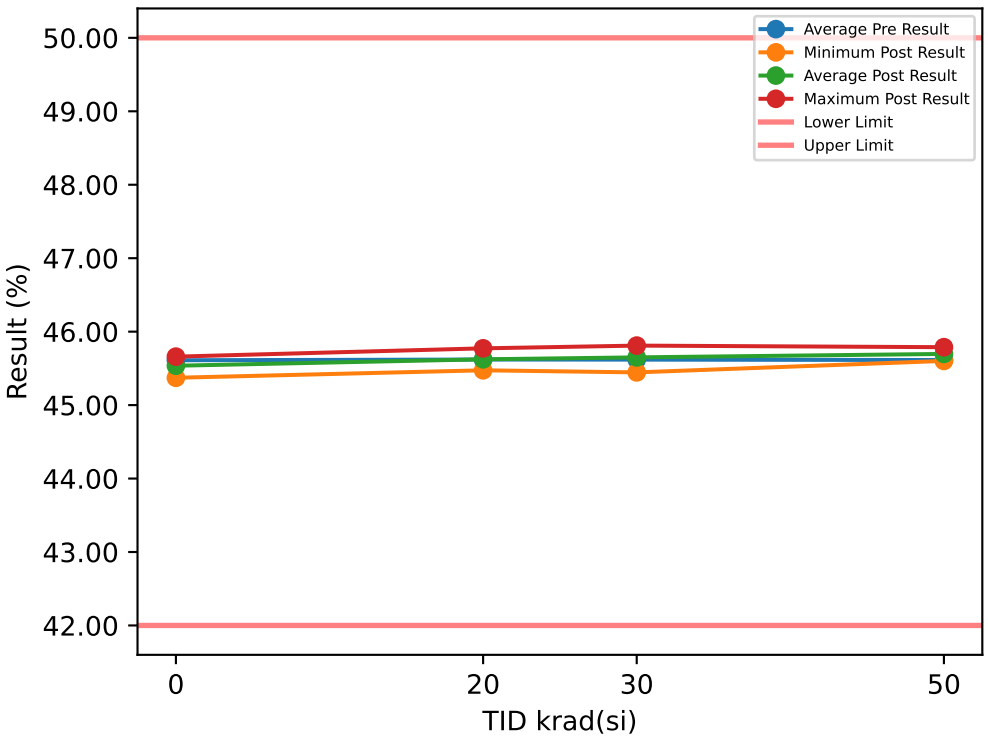
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	45.673	45.694	0.0206
2	20	Unbiased	45.624	45.691	0.0675
3	50	Biased	45.703	45.686	-0.0174
4	30	Unbiased	45.75	45.733	-0.0168
5	50	Unbiased	45.663	45.79	0.1271
6	30	Biased	45.646	45.816	0.1703
7	50	Biased	45.724	45.666	-0.0588
8	30	Unbiased	45.649	45.498	-0.1508
9	20	Unbiased	45.644	45.719	0.0746
10	50	Biased	45.516	45.774	0.2579
11	30	Biased	45.635	45.707	0.0723
12	0	Correlation	45.695	45.68	-0.0148
13	0	Correlation	45.444	45.395	-0.0493
14	50	Unbiased	45.601	45.733	0.1323
15	20	Biased	45.751	45.776	0.0253
16	20	Unbiased	45.717	45.597	-0.1203
17	20	Biased	45.65	45.602	-0.048
18	20	Unbiased	45.475	45.503	0.0284
19	20	Biased	45.639	45.556	-0.0824
20	50	Unbiased	45.713	45.708	-0.0051
21	0	Correlation	45.666	45.594	-0.0714
22	50	Unbiased	45.553	45.701	0.1483
23	0	Correlation	45.696	45.545	-0.1514
24	20	Biased	45.683	45.544	-0.1387
26	50	Biased	45.552	45.63	0.0776
27	30	Unbiased	45.695	45.703	0.0083
28	30	Biased	45.624	45.558	-0.0663
29	30	Unbiased	45.597	45.585	-0.0121
30	20	Biased	45.535	45.736	0.2016
31	30	Unbiased	45.642	45.486	-0.1553
33	30	Biased	45.678	45.823	0.1446
34	50	Unbiased	45.659	45.711	0.0519
35	20	Unbiased	45.649	45.706	0.057
41	30	Biased	45.465	45.749	0.2837

Test Statistics (%)

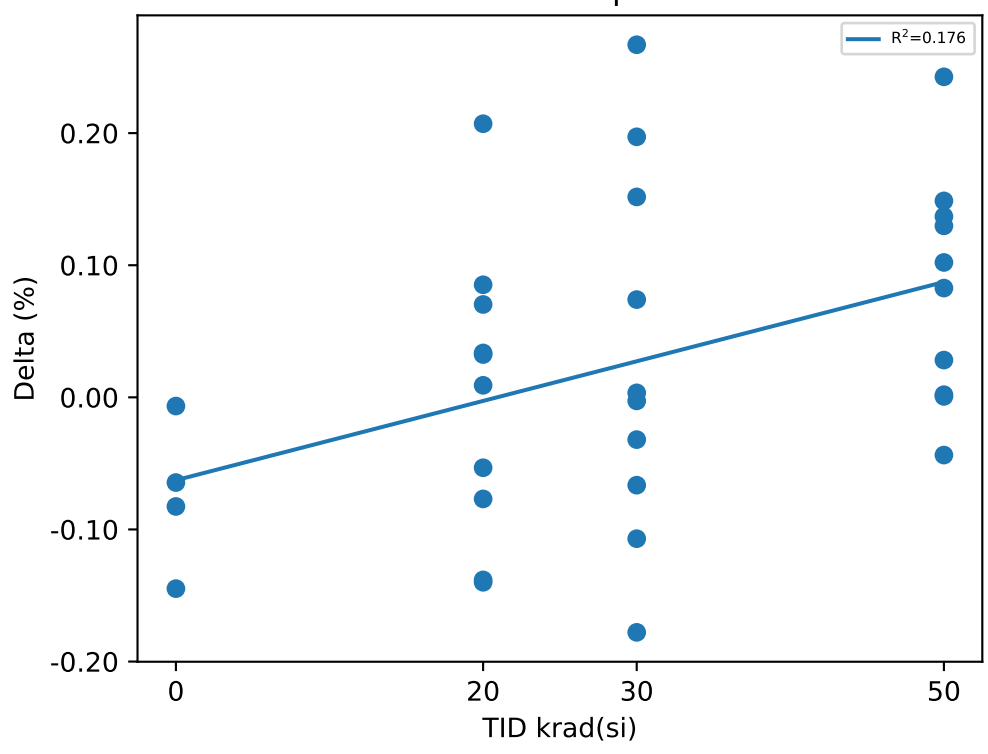
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	45.444	45.625	45.696	0.12153	45.395	45.553	45.68	0.11959	-0.1514	-0.071725	-0.0148	0.057999
20	45.475	45.637	45.751	0.080795	45.503	45.643	45.776	0.093684	-0.1387	0.0065	0.2016	0.10426
30	45.465	45.638	45.75	0.074022	45.486	45.666	45.823	0.12487	-0.1553	0.02779	0.2837	0.14129
50	45.516	45.636	45.724	0.074965	45.63	45.709	45.79	0.047643	-0.0588	0.07344	0.2579	0.094959

Device Test: 27.32 LEVEL|DCL/OUT/14/14/0/0/5/1MHz//@MAX_DCL_50

TID vs Result Stats



TID vs Post - Pre Exposure Delta



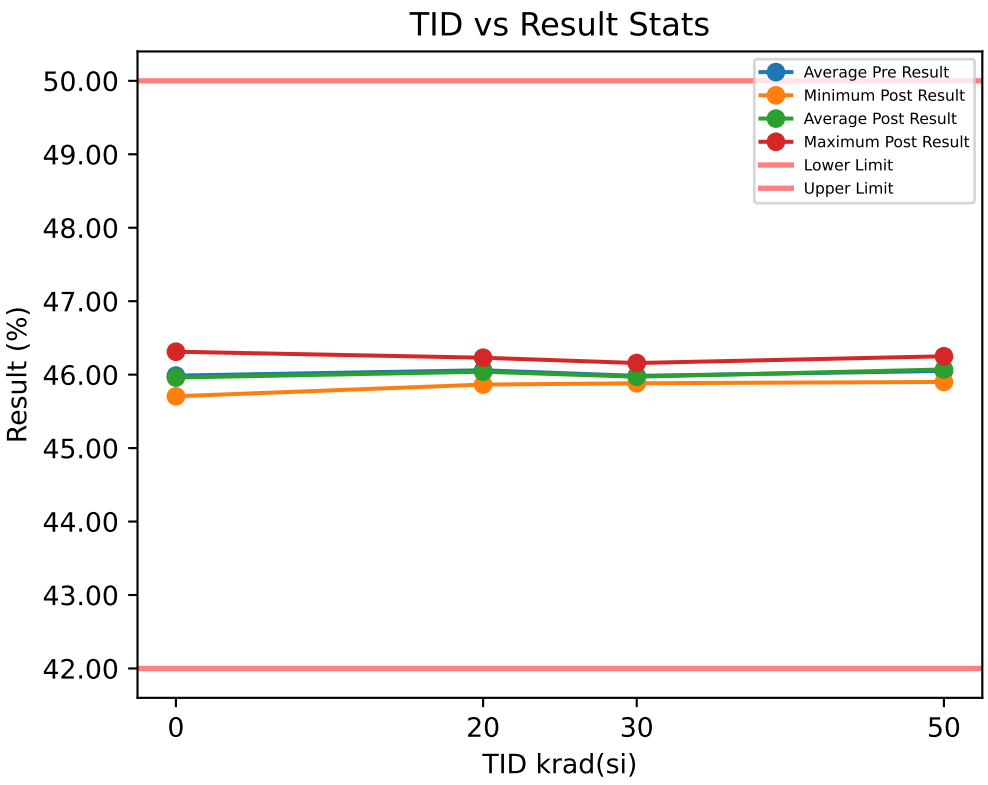
Test Results (Lower Limit = 42.0, Upper Limit = 50.0 (%))

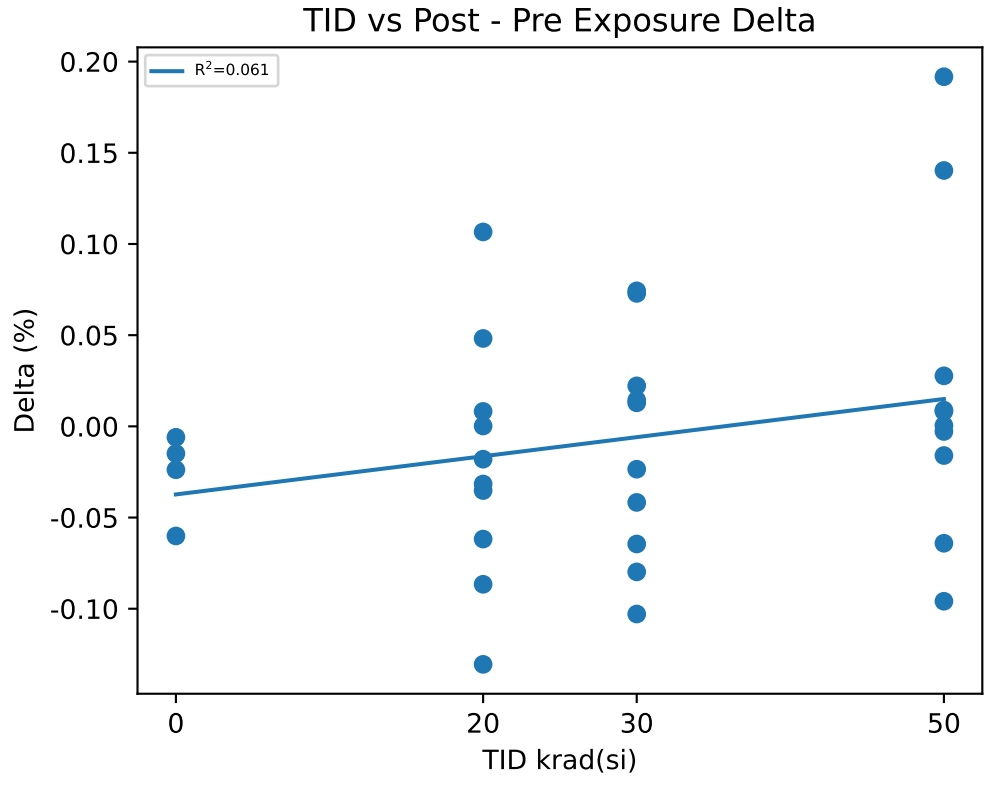
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	45.666	45.695	0.0282
2	20	Unbiased	45.619	45.689	0.0703
3	50	Biased	45.654	45.655	0.0007
4	30	Unbiased	45.744	45.712	-0.032
5	50	Unbiased	45.64	45.789	0.1487
6	30	Biased	45.613	45.81	0.1972
7	50	Biased	45.699	45.656	-0.0437
8	30	Unbiased	45.622	45.515	-0.107
9	20	Unbiased	45.626	45.711	0.0852
10	50	Biased	45.512	45.755	0.2426
11	30	Biased	45.614	45.688	0.074
12	0	Correlation	45.666	45.66	-0.0066
13	0	Correlation	45.437	45.372	-0.0645
14	50	Unbiased	45.58	45.71	0.1298
15	20	Biased	45.739	45.773	0.0336
16	20	Unbiased	45.692	45.554	-0.1382
17	20	Biased	45.63	45.577	-0.0533
18	20	Unbiased	45.465	45.474	0.0091
19	20	Biased	45.623	45.547	-0.0769
20	50	Unbiased	45.683	45.685	0.002
21	0	Correlation	45.663	45.58	-0.0826
22	50	Unbiased	45.558	45.695	0.1369
23	0	Correlation	45.677	45.532	-0.1448
24	20	Biased	45.654	45.514	-0.14
26	50	Biased	45.519	45.602	0.0827
27	30	Unbiased	45.683	45.686	0.0034
28	30	Biased	45.605	45.538	-0.0665
29	30	Unbiased	45.582	45.58	-0.0027
30	20	Biased	45.507	45.714	0.2071
31	30	Unbiased	45.623	45.445	-0.1779
33	30	Biased	45.652	45.804	0.1517
34	50	Unbiased	45.624	45.726	0.1021
35	20	Unbiased	45.648	45.68	0.0324
41	30	Biased	45.452	45.719	0.2669

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	45.437	45.611	45.677	0.11611	45.372	45.536	45.66	0.12122	-0.1448	-0.074625	-0.0066	0.056915
20	45.465	45.62	45.739	0.08055	45.474	45.623	45.773	0.10164	-0.14	0.00293	0.2071	0.10787
30	45.452	45.619	45.744	0.074788	45.445	45.65	45.81	0.12392	-0.1779	0.03071	0.2669	0.14053
50	45.512	45.614	45.699	0.067461	45.602	45.697	45.789	0.053168	-0.0437	0.083	0.2426	0.086692

Device Test: 27.33 LEVEL|WRST_MAX/OUT/4.5/4.5/0/0/4.5/100kHz//@MAX_DCL_50





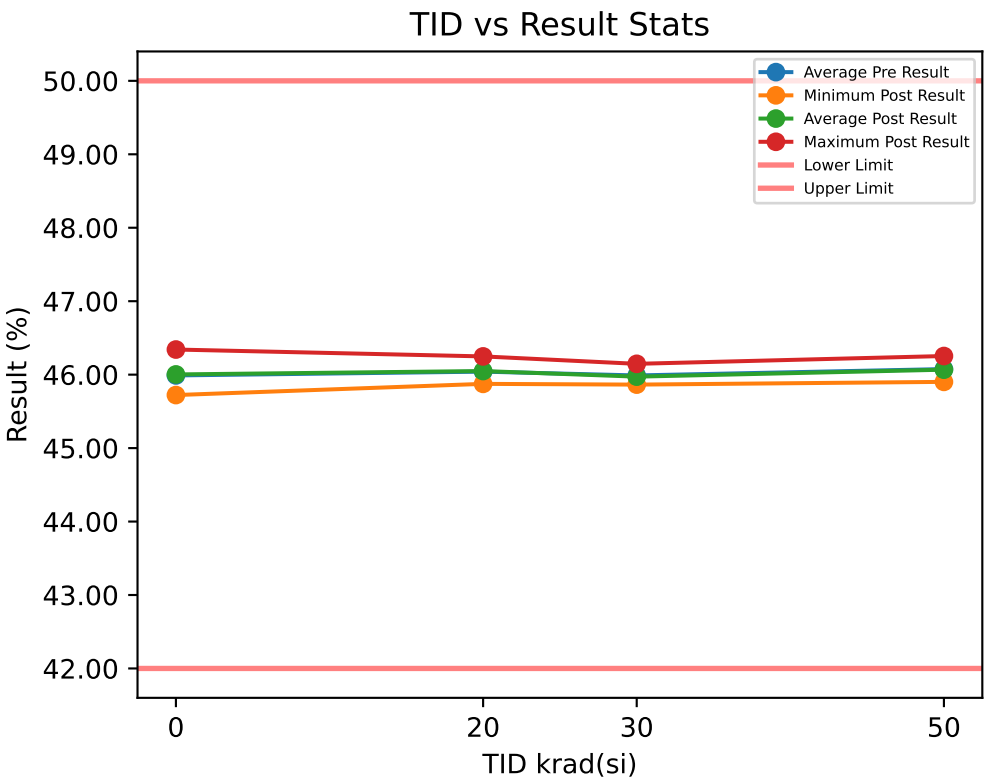
Test Results (Lower Limit = 42.0, Upper Limit = 50.0 (%))

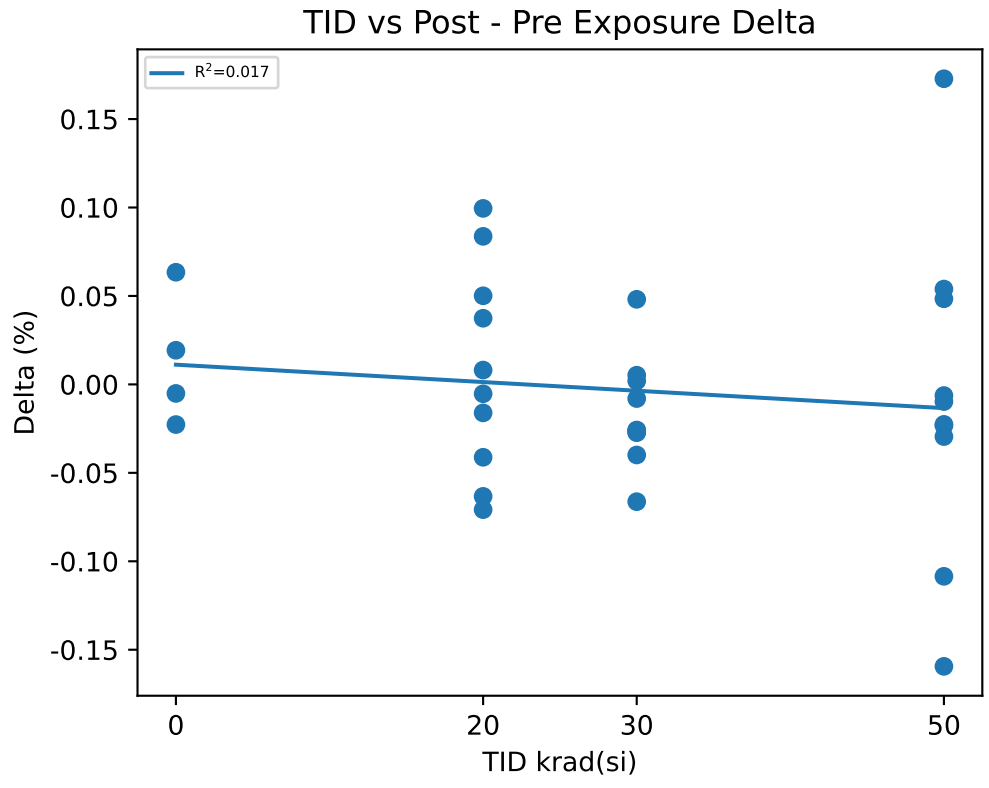
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	46.008	45.944	-0.0641
2	20	Unbiased	46.102	46.209	0.1066
3	50	Biased	45.979	46.171	0.1917
4	30	Unbiased	45.962	46.034	0.0729
5	50	Unbiased	46.211	46.22	0.0089
6	30	Biased	46.182	46.158	-0.0235
7	50	Biased	46.093	46.093	0.0005
8	30	Unbiased	45.886	45.899	0.0129
9	20	Unbiased	46.051	45.989	-0.0618
10	50	Biased	45.892	45.901	0.0082
11	30	Biased	45.976	45.896	-0.0798
12	0	Correlation	45.886	45.88	-0.006
13	0	Correlation	45.72	45.706	-0.0149
14	50	Unbiased	46.081	45.985	-0.0959
15	20	Biased	46.163	46.077	-0.0866
16	20	Unbiased	46.133	46.101	-0.0316
17	20	Biased	46.182	46.23	0.0482
18	20	Unbiased	45.857	45.865	0.0082
19	20	Biased	45.999	45.869	-0.1305
20	50	Unbiased	46.015	45.999	-0.016
21	0	Correlation	46.336	46.312	-0.0238
22	50	Unbiased	46.038	46.066	0.0277
23	0	Correlation	46.004	45.944	-0.0601
24	20	Biased	46.015	45.98	-0.0352
26	50	Biased	45.939	46.079	0.1403
27	30	Unbiased	46.043	45.978	-0.0645
28	30	Biased	45.809	45.883	0.0743
29	30	Unbiased	45.91	45.925	0.0144
30	20	Biased	46.095	46.095	0.0002
31	30	Unbiased	46.005	45.902	-0.1029
33	30	Biased	46.051	46.073	0.0222
34	50	Unbiased	46.253	46.25	-0.0028
35	20	Unbiased	45.999	45.981	-0.018
41	30	Biased	46.011	45.969	-0.0417

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	45.72	45.987	46.336	0.26029	45.706	45.96	46.312	0.25521	-0.0601	-0.0262	-0.006	0.02374
20	45.857	46.06	46.182	0.09697	45.865	46.04	46.23	0.12584	-0.1305	-0.02005	0.1066	0.067202
30	45.809	45.983	46.182	0.10247	45.883	45.972	46.158	0.091282	-0.1029	-0.01157	0.0743	0.061256
50	45.892	46.051	46.253	0.11311	45.901	46.071	46.25	0.11664	-0.0959	0.01985	0.1917	0.086266

Device Test: 27.34 LEVEL|WRST_MAX/OUT/5/5/0/0/5/100kHz//@MAX_DCL_50





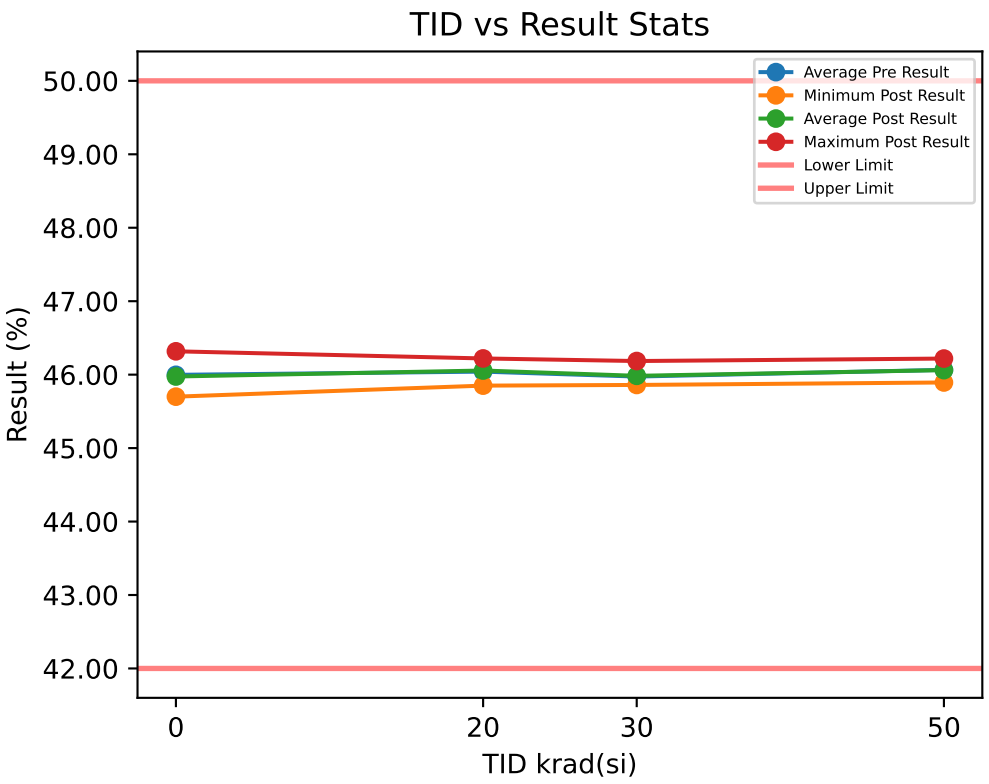
Test Results (Lower Limit = 42.0, Upper Limit = 50.0 (%))

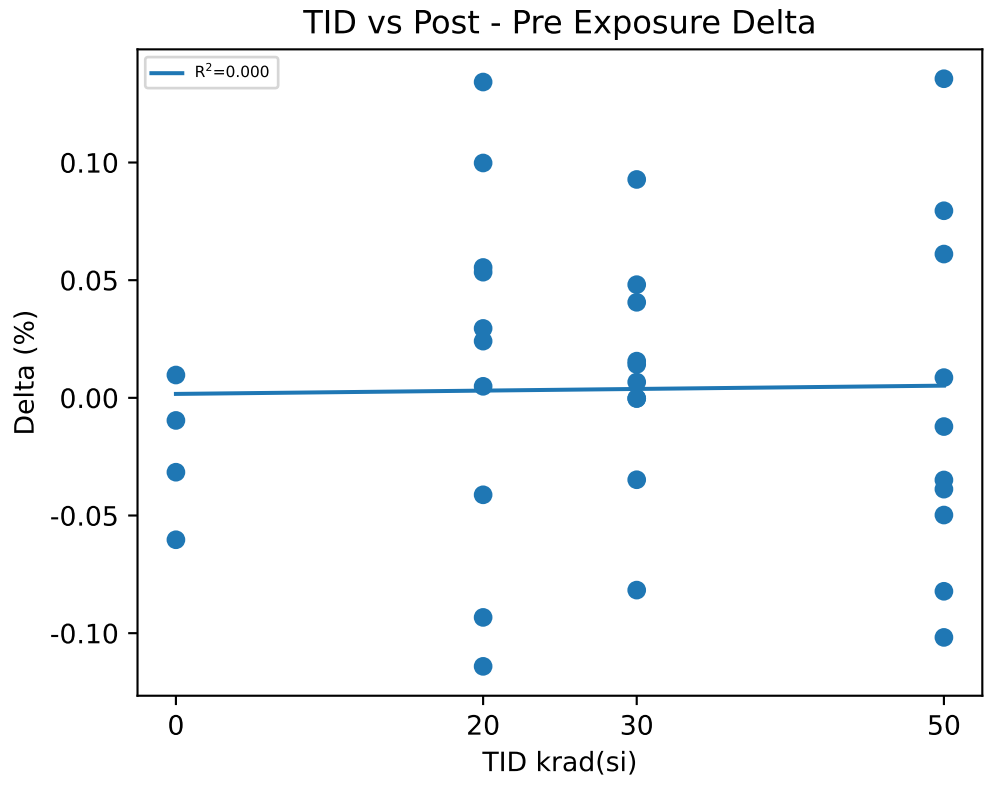
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	45.958	45.935	-0.0226
2	20	Unbiased	46.095	46.194	0.0995
3	50	Biased	46.043	46.216	0.1728
4	30	Unbiased	46.001	45.993	-0.008
5	50	Unbiased	46.239	46.215	-0.0233
6	30	Biased	46.173	46.147	-0.0258
7	50	Biased	46.071	46.119	0.0484
8	30	Unbiased	45.875	45.923	0.0481
9	20	Unbiased	46.043	45.972	-0.0708
10	50	Biased	45.908	45.902	-0.0063
11	30	Biased	45.891	45.896	0.0052
12	0	Correlation	45.931	45.909	-0.0227
13	0	Correlation	45.727	45.722	-0.0051
14	50	Unbiased	46.063	45.955	-0.1085
15	20	Biased	46.111	46.095	-0.0161
16	20	Unbiased	46.157	46.116	-0.0412
17	20	Biased	46.198	46.248	0.0501
18	20	Unbiased	45.866	45.874	0.0081
19	20	Biased	45.956	45.893	-0.0633
20	50	Unbiased	46.15	45.99	-0.1594
21	0	Correlation	46.323	46.342	0.0193
22	50	Unbiased	46.027	46.018	-0.0097
23	0	Correlation	45.976	46.039	0.0634
24	20	Biased	45.993	45.988	-0.0053
26	50	Biased	46.017	46.071	0.0539
27	30	Unbiased	45.988	45.99	0.002
28	30	Biased	45.904	45.864	-0.0399
29	30	Unbiased	45.944	45.917	-0.0269
30	20	Biased	46.018	46.101	0.0837
31	30	Unbiased	46.01	45.944	-0.0663
33	30	Biased	46.099	46.072	-0.0273
34	50	Unbiased	46.283	46.254	-0.0295
35	20	Unbiased	45.972	46.009	0.0374
41	30	Biased	46.005	45.979	-0.026

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	45.727	45.989	46.323	0.24717	45.722	46.003	46.342	0.26072	-0.0227	0.013725	0.0634	0.037327
20	45.866	46.041	46.198	0.10067	45.874	46.049	46.248	0.12296	-0.0708	0.00821	0.0995	0.058888
30	45.875	45.989	46.173	0.093485	45.864	45.973	46.147	0.084982	-0.0663	-0.01649	0.0481	0.03071
50	45.908	46.076	46.283	0.11737	45.902	46.067	46.254	0.12795	-0.1594	-0.00842	0.1728	0.090454

Device Test: 27.35 LEVEL|WRST_MAX/OUT/12/12/0/0/5/100kHz//@MAX_DCL_50





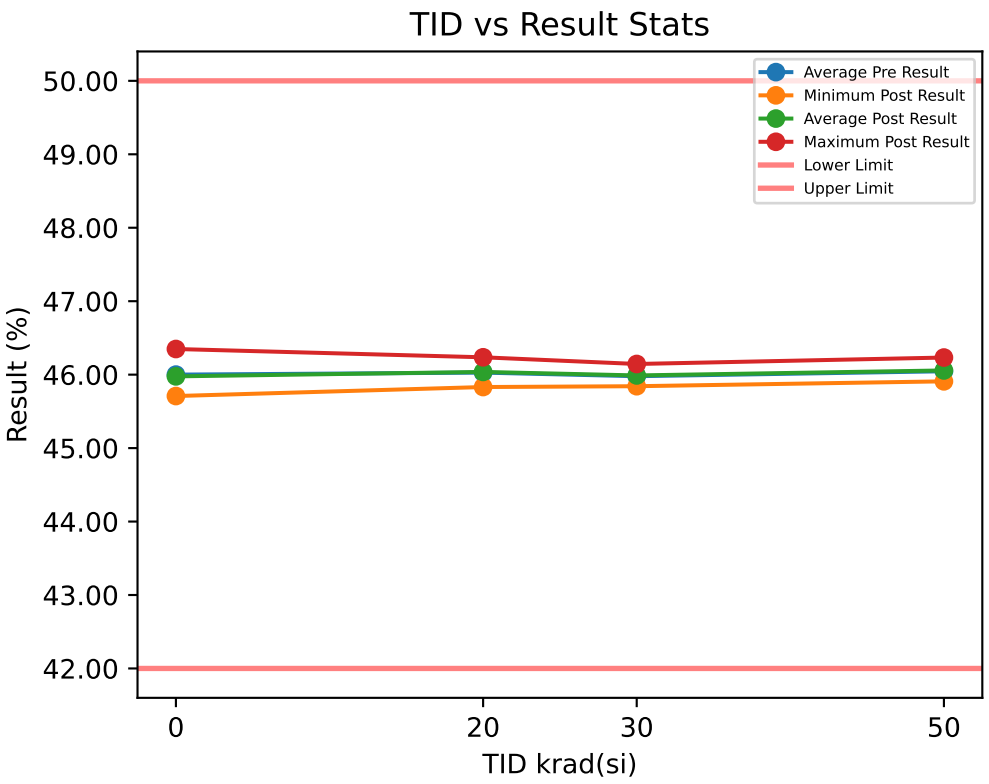
Test Results (Lower Limit = 42.0, Upper Limit = 50.0 (%))

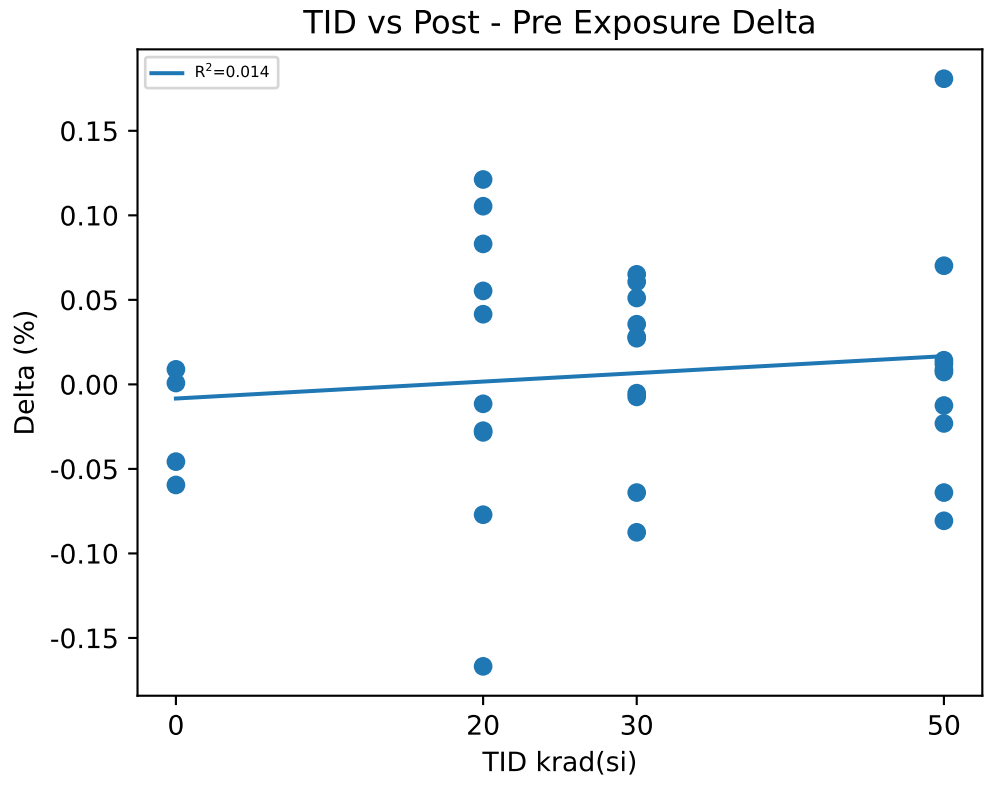
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	45.984	45.949	-0.0349
2	20	Unbiased	46.058	46.192	0.1342
3	50	Biased	46.047	46.182	0.1356
4	30	Unbiased	46.002	46.095	0.0928
5	50	Unbiased	46.196	46.184	-0.0122
6	30	Biased	46.137	46.185	0.0481
7	50	Biased	46.025	46.105	0.0795
8	30	Unbiased	45.877	45.917	0.0406
9	20	Unbiased	46.052	46.011	-0.0412
10	50	Biased	45.885	45.893	0.0086
11	30	Biased	45.909	45.915	0.0067
12	0	Correlation	45.964	45.903	-0.0603
13	0	Correlation	45.691	45.7	0.0097
14	50	Unbiased	46.066	45.984	-0.0822
15	20	Biased	46.071	46.1	0.0295
16	20	Unbiased	46.157	46.161	0.0049
17	20	Biased	46.197	46.221	0.0241
18	20	Unbiased	45.868	45.923	0.0554
19	20	Biased	45.965	45.851	-0.1141
20	50	Unbiased	46.118	46.016	-0.1018
21	0	Correlation	46.349	46.318	-0.0316
22	50	Unbiased	46.047	45.997	-0.0498
23	0	Correlation	45.987	45.977	-0.0096
24	20	Biased	46.097	46.003	-0.0933
26	50	Biased	46.026	46.087	0.0611
27	30	Unbiased	45.984	45.983	-0.0003
28	30	Biased	45.941	45.86	-0.0817
29	30	Unbiased	45.889	45.889	-0.0002
30	20	Biased	46.065	46.119	0.0534
31	30	Unbiased	45.932	45.897	-0.0348
33	30	Biased	46.089	46.103	0.0142
34	50	Unbiased	46.258	46.219	-0.0388
35	20	Unbiased	45.882	45.982	0.0998
41	30	Biased	45.98	45.995	0.0156

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	45.691	45.998	46.349	0.27032	45.7	45.975	46.318	0.25694	-0.0603	-0.02295	0.0097	0.030078
20	45.868	46.041	46.197	0.10717	45.851	46.056	46.221	0.12136	-0.1141	0.01527	0.1342	0.079201
30	45.877	45.974	46.137	0.084672	45.86	45.984	46.185	0.10974	-0.0817	0.0101	0.0928	0.047057
50	45.885	46.065	46.258	0.10538	45.893	46.062	46.219	0.11053	-0.1018	-0.00349	0.1356	0.075178

Device Test: 27.36 LEVEL|WRST_MAX/OUT/14/14/0/0/5/100kHz//@MAX_DCL_50





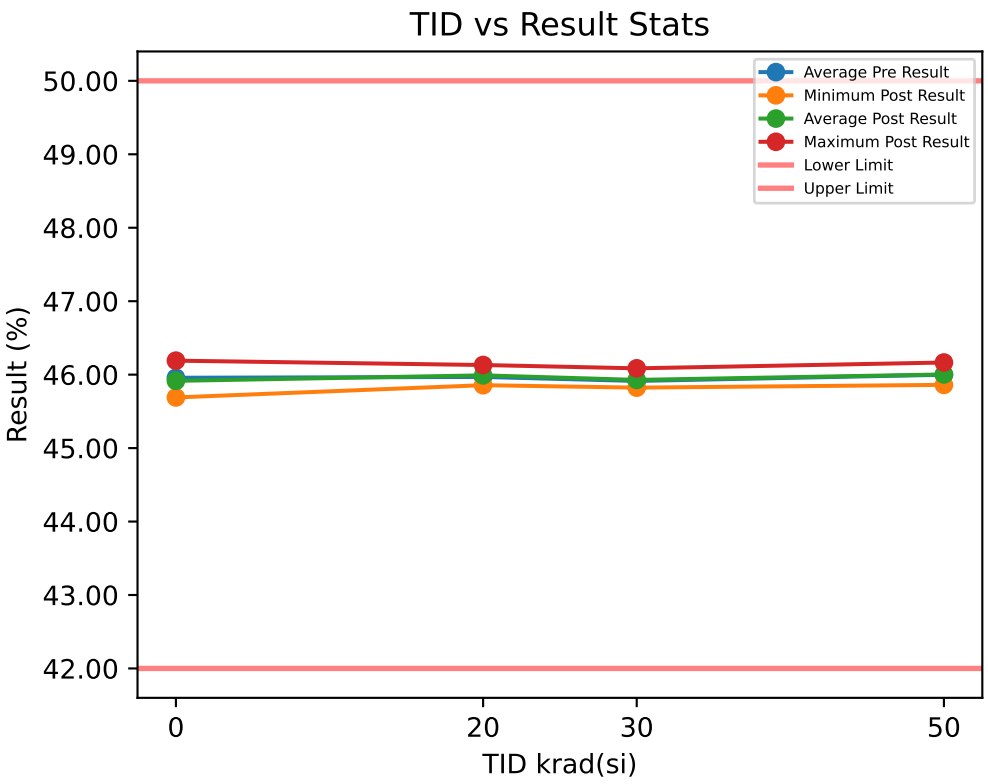
Test Results (Lower Limit = 42.0, Upper Limit = 50.0 (%))

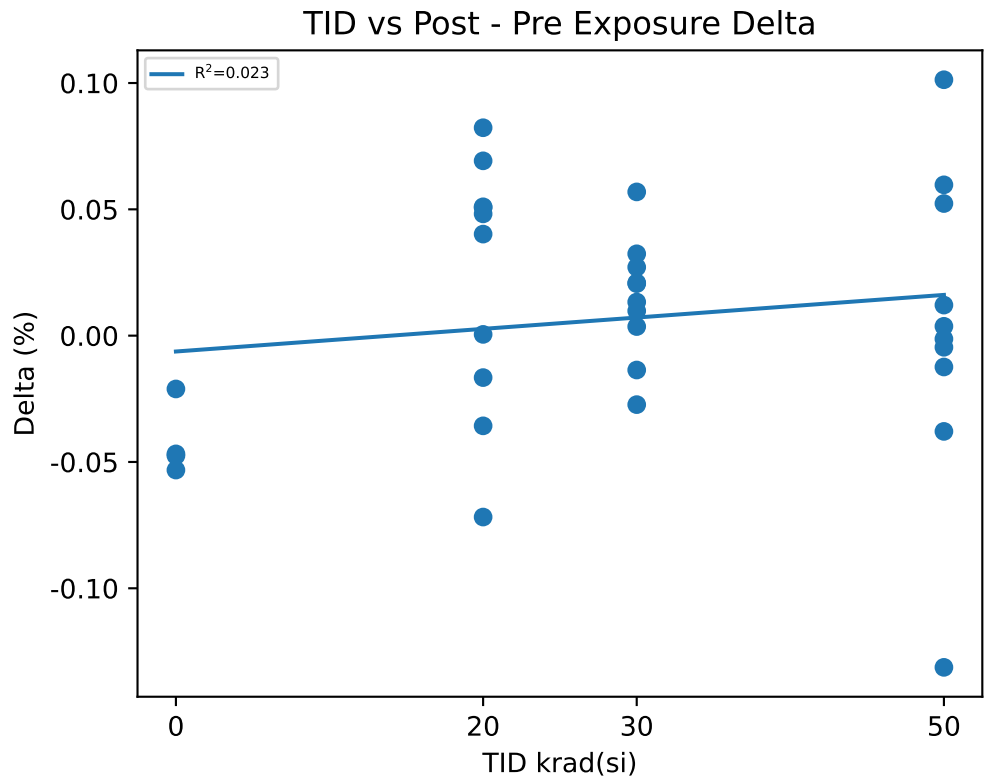
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	45.932	45.909	-0.0231
2	20	Unbiased	46.072	46.193	0.1212
3	50	Biased	45.953	46.134	0.1808
4	30	Unbiased	46.056	46.051	-0.0052
5	50	Unbiased	46.194	46.181	-0.0125
6	30	Biased	46.153	46.145	-0.0074
7	50	Biased	46.076	46.084	0.0073
8	30	Unbiased	45.885	45.95	0.0651
9	20	Unbiased	46.047	46.018	-0.0284
10	50	Biased	45.903	45.912	0.0088
11	30	Biased	45.886	45.913	0.0273
12	0	Correlation	45.953	45.893	-0.0595
13	0	Correlation	45.7	45.709	0.0089
14	50	Unbiased	46.069	46.005	-0.064
15	20	Biased	46.078	46.066	-0.0115
16	20	Unbiased	46.143	46.116	-0.0274
17	20	Biased	46.195	46.236	0.0415
18	20	Unbiased	45.781	45.886	0.1054
19	20	Biased	45.998	45.831	-0.1668
20	50	Unbiased	46.069	45.988	-0.0807
21	0	Correlation	46.348	46.349	0.0008
22	50	Unbiased	45.986	46.056	0.0702
23	0	Correlation	46.001	45.955	-0.0457
24	20	Biased	46.056	45.979	-0.0771
26	50	Biased	46.056	46.07	0.0143
27	30	Unbiased	45.998	46.026	0.0281
28	30	Biased	45.907	45.843	-0.064
29	30	Unbiased	45.887	45.923	0.0356
30	20	Biased	46.029	46.084	0.0553
31	30	Unbiased	46.003	45.916	-0.0875
33	30	Biased	46.05	46.111	0.0607
34	50	Unbiased	46.221	46.233	0.0121
35	20	Unbiased	45.88	45.963	0.0831
41	30	Biased	45.964	46.015	0.0511

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	45.7	46	46.348	0.26685	45.709	45.977	46.349	0.26952	-0.0595	-0.023875	0.0089	0.033806
20	45.781	46.028	46.195	0.12049	45.831	46.037	46.236	0.12806	-0.1668	0.00953	0.1212	0.089463
30	45.885	45.979	46.153	0.09027	45.843	45.989	46.145	0.096258	-0.0875	0.01038	0.0651	0.051739
50	45.903	46.046	46.221	0.10556	45.909	46.057	46.233	0.10729	-0.0807	0.01132	0.1808	0.073117

Device Test: 27.37 LEVEL|WRST_MAX/OUT/4.5/4.5/0/0/4.5/200kHz//@MAX_DCL_50





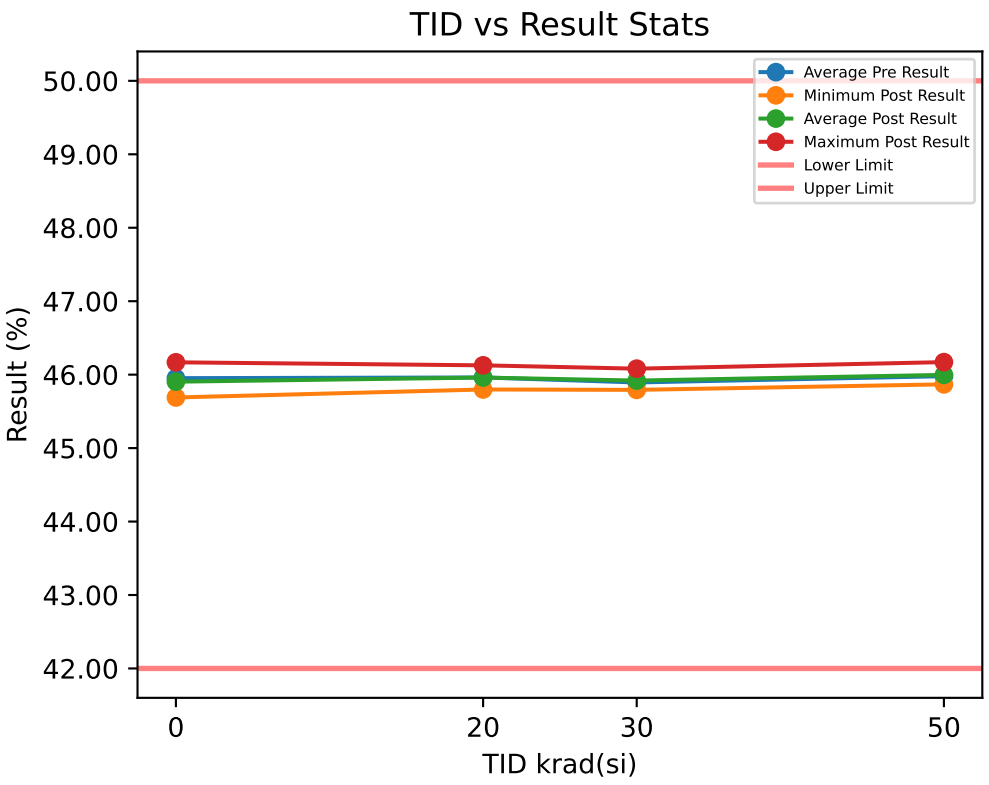
Test Results (Lower Limit = 42.0, Upper Limit = 50.0 (%))

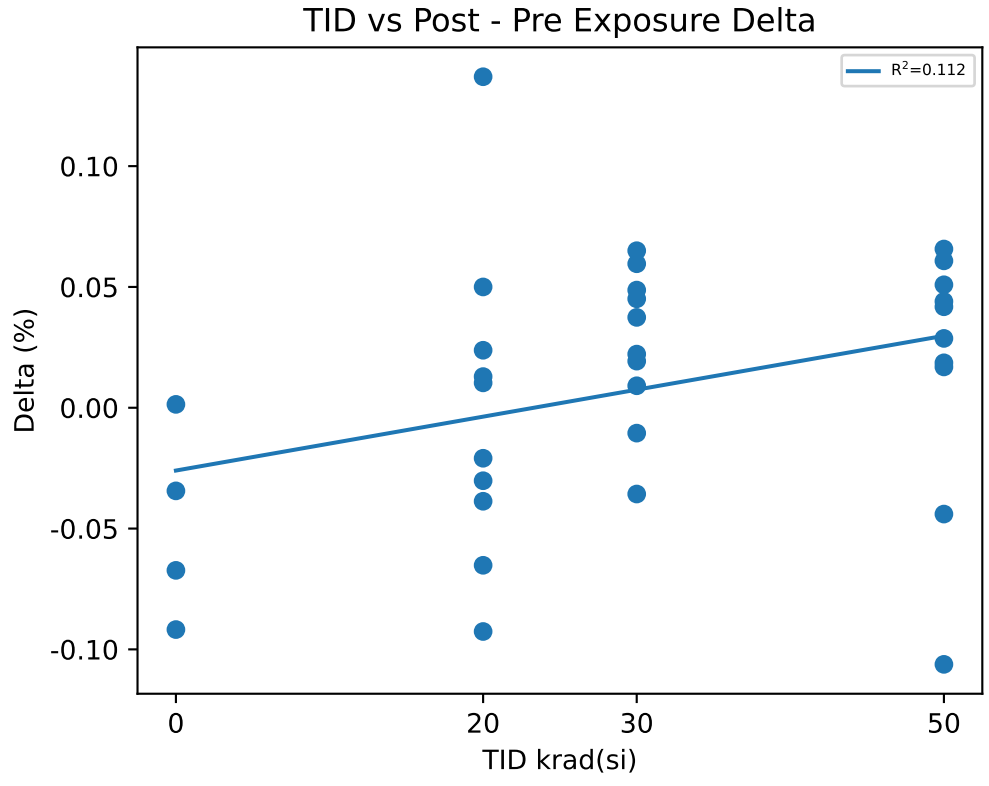
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	45.946	45.933	-0.0124
2	20	Unbiased	46.081	46.131	0.0507
3	50	Biased	46.006	46.065	0.0597
4	30	Unbiased	45.972	45.976	0.0036
5	50	Unbiased	46.114	46.113	-0.0013
6	30	Biased	46.076	46.086	0.0098
7	50	Biased	45.998	46.051	0.0523
8	30	Unbiased	45.842	45.898	0.0569
9	20	Unbiased	46.021	45.95	-0.0718
10	50	Biased	45.866	45.861	-0.0046
11	30	Biased	45.85	45.863	0.0133
12	0	Correlation	45.907	45.86	-0.0468
13	0	Correlation	45.711	45.69	-0.0211
14	50	Unbiased	45.949	45.911	-0.0379
15	20	Biased	46.013	46.064	0.051
16	20	Unbiased	46.05	46.014	-0.0357
17	20	Biased	46.094	46.095	0.0005
18	20	Unbiased	45.828	45.897	0.0692
19	20	Biased	45.816	45.856	0.0402
20	50	Unbiased	46.047	45.915	-0.1313
21	0	Correlation	46.238	46.191	-0.0475
22	50	Unbiased	45.971	45.974	0.0037
23	0	Correlation	45.975	45.922	-0.0532
24	20	Biased	45.939	45.923	-0.0166
26	50	Biased	45.936	46.038	0.1013
27	30	Unbiased	45.976	45.963	-0.0136
28	30	Biased	45.802	45.823	0.0209
29	30	Unbiased	45.837	45.858	0.0206
30	20	Biased	45.95	46.033	0.0823
31	30	Unbiased	45.875	45.848	-0.0273
33	30	Biased	45.982	46.014	0.0324
34	50	Unbiased	46.153	46.165	0.0121
35	20	Unbiased	45.894	45.943	0.0482
41	30	Biased	45.929	45.956	0.0271

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	45.711	45.958	46.238	0.21788	45.69	45.916	46.191	0.20795	-0.0532	-0.04215	-0.0211	0.014323
20	45.816	45.969	46.094	0.099638	45.856	45.991	46.131	0.090454	-0.0718	0.0218	0.0823	0.05014
30	45.802	45.914	46.076	0.086736	45.823	45.928	46.086	0.084439	-0.0273	0.01437	0.0569	0.023651
50	45.866	45.998	46.153	0.086364	45.861	46.003	46.165	0.098691	-0.1313	0.00416	0.1013	0.062717

Device Test: 27.38 LEVEL|WRST_MAX/OUT/5/5/0/0/5/200kHz//@MAX_DCL_50





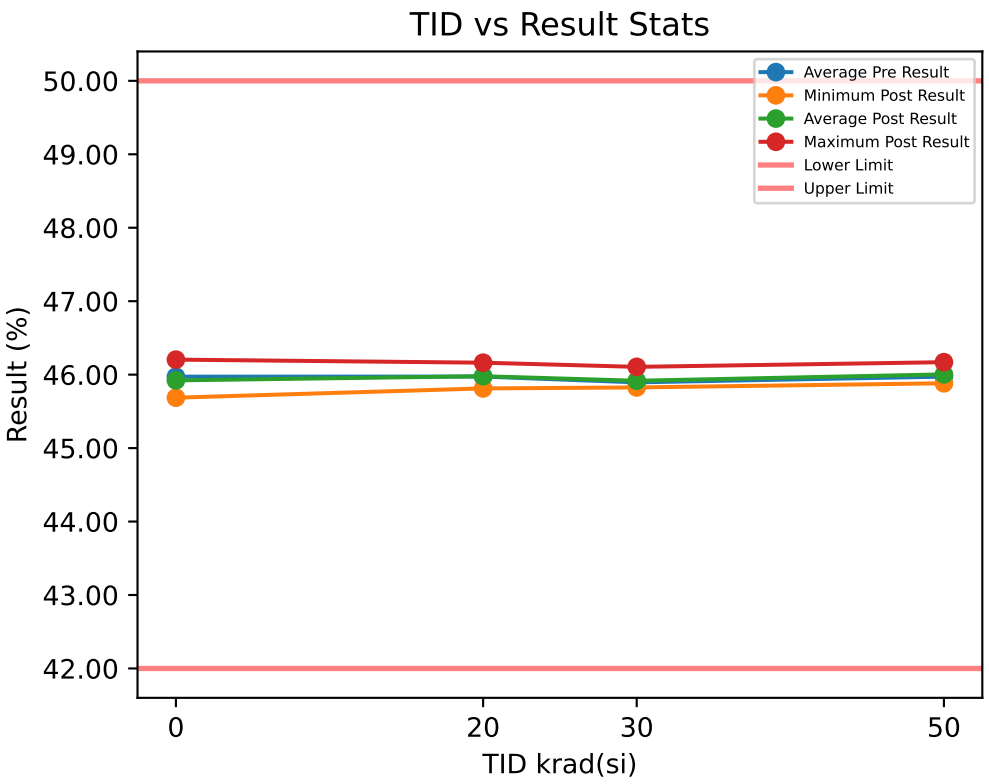
Test Results (Lower Limit = 42.0, Upper Limit = 50.0 (%))

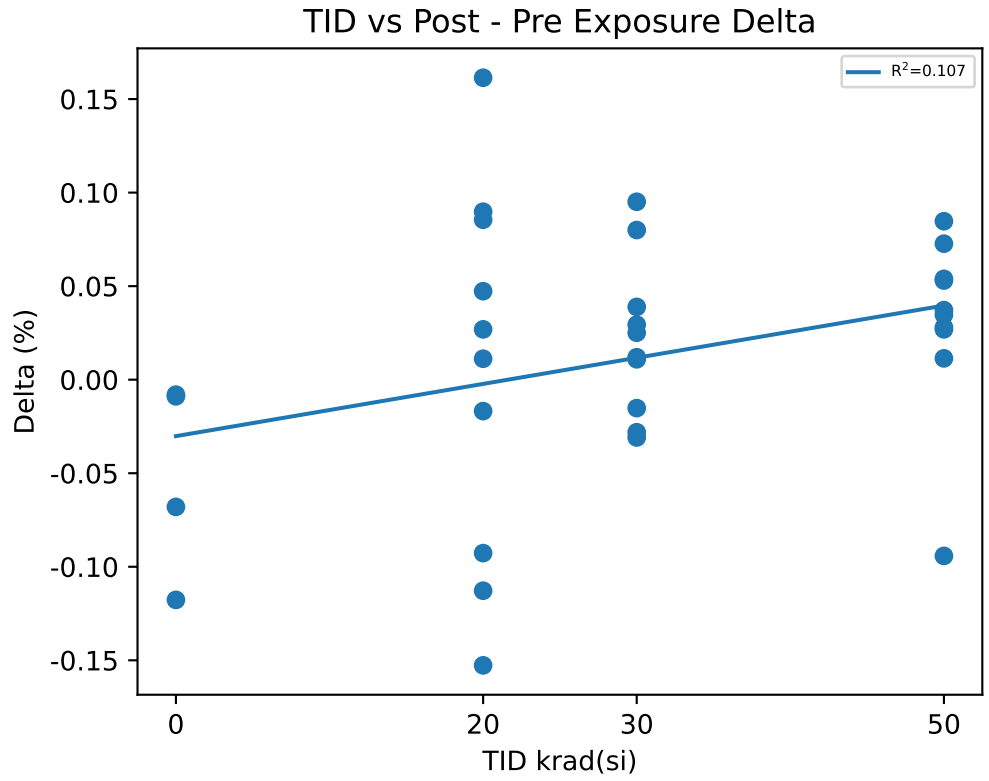
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	45.91	45.929	0.0186
2	20	Unbiased	45.99	46.127	0.137
3	50	Biased	45.993	46.054	0.0608
4	30	Unbiased	45.944	46.009	0.065
5	50	Unbiased	46.083	46.112	0.0287
6	30	Biased	46.033	46.081	0.0487
7	50	Biased	45.961	46.026	0.0657
8	30	Unbiased	45.826	45.886	0.0596
9	20	Unbiased	46.018	45.926	-0.0926
10	50	Biased	45.817	45.868	0.0509
11	30	Biased	45.821	45.843	0.0222
12	0	Correlation	45.935	45.867	-0.0673
13	0	Correlation	45.688	45.689	0.0014
14	50	Unbiased	45.952	45.908	-0.044
15	20	Biased	46.007	46.017	0.0103
16	20	Unbiased	46.047	46.008	-0.0387
17	20	Biased	46.083	46.062	-0.0209
18	20	Unbiased	45.815	45.828	0.0129
19	20	Biased	45.828	45.798	-0.0302
20	50	Unbiased	46.023	45.916	-0.1062
21	0	Correlation	46.202	46.168	-0.0344
22	50	Unbiased	45.935	45.979	0.044
23	0	Correlation	45.984	45.892	-0.0918
24	20	Biased	45.981	45.916	-0.0652
26	50	Biased	45.988	46.005	0.0169
27	30	Unbiased	45.91	45.955	0.0451
28	30	Biased	45.818	45.855	0.0374
29	30	Unbiased	45.863	45.883	0.0193
30	20	Biased	45.965	46.016	0.05
31	30	Unbiased	45.828	45.793	-0.0357
33	30	Biased	45.988	45.977	-0.0105
34	50	Unbiased	46.129	46.17	0.0418
35	20	Unbiased	45.884	45.907	0.0238
41	30	Biased	45.904	45.913	0.0091

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	45.688	45.952	46.202	0.21126	45.689	45.904	46.168	0.19778	-0.0918	-0.048025	0.0014	0.040481
20	45.815	45.962	46.083	0.090506	45.798	45.961	46.127	0.10345	-0.0926	-0.00136	0.137	0.064775
30	45.818	45.893	46.033	0.076043	45.793	45.919	46.081	0.086674	-0.0357	0.02602	0.065	0.031875
50	45.817	45.979	46.129	0.087826	45.868	45.997	46.17	0.096378	-0.1062	0.01772	0.0657	0.053559

Device Test: 27.39 LEVEL|WRST_MAX/OUT/12/12/0/0/5/200kHz//@MAX_DCL_50





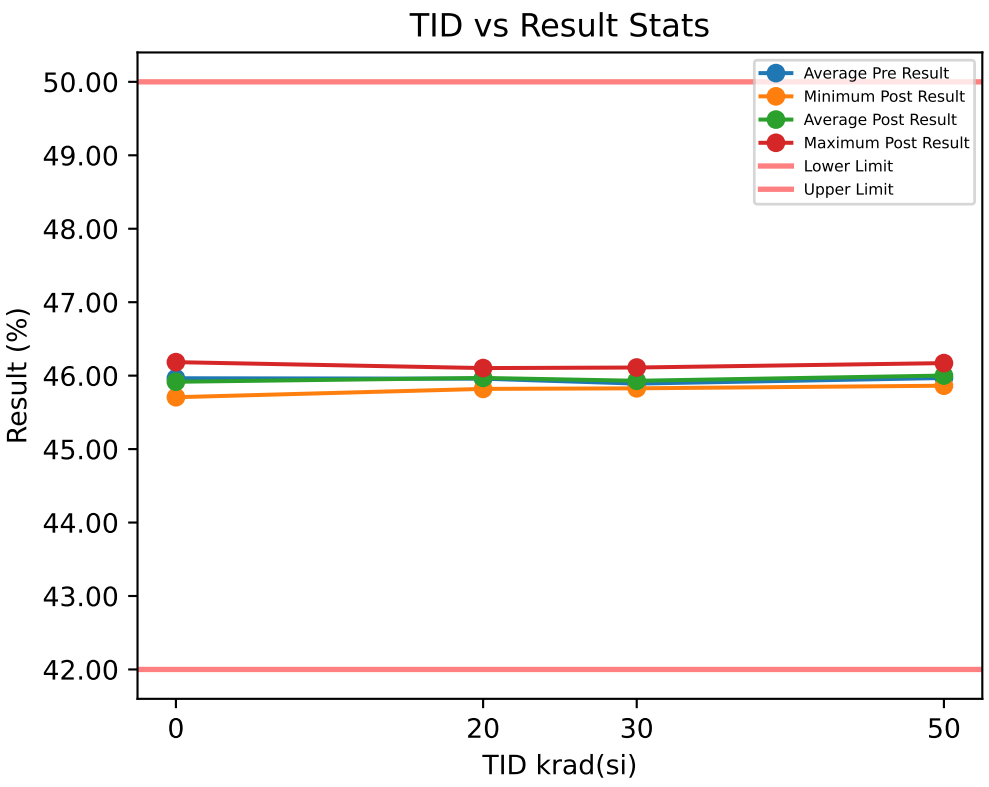
Test Results (Lower Limit = 42.0, Upper Limit = 50.0 (%))

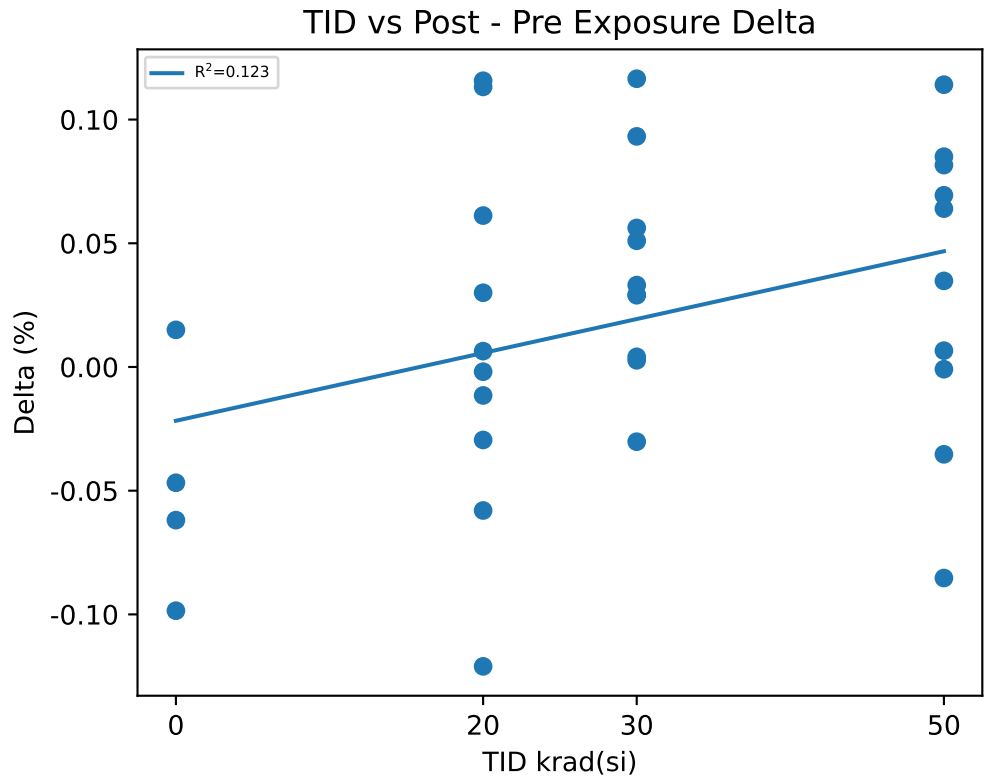
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	45.916	45.951	0.0347
2	20	Unbiased	46.001	46.163	0.1614
3	50	Biased	45.983	46.068	0.0847
4	30	Unbiased	45.962	45.973	0.0109
5	50	Unbiased	46.102	46.129	0.0269
6	30	Biased	46.011	46.106	0.0951
7	50	Biased	46.006	46.018	0.0114
8	30	Unbiased	45.798	45.879	0.08
9	20	Unbiased	46.041	45.928	-0.1128
10	50	Biased	45.81	45.882	0.0727
11	30	Biased	45.856	45.868	0.012
12	0	Correlation	45.941	45.933	-0.008
13	0	Correlation	45.695	45.686	-0.0089
14	50	Unbiased	45.917	45.945	0.028
15	20	Biased	46.008	46.035	0.0269
16	20	Unbiased	46.008	46.019	0.0112
17	20	Biased	46.099	46.082	-0.0168
18	20	Unbiased	45.795	45.88	0.0855
19	20	Biased	45.905	45.812	-0.0927
20	50	Unbiased	46.002	45.907	-0.0942
21	0	Correlation	46.273	46.205	-0.068
22	50	Unbiased	45.903	45.94	0.0372
23	0	Correlation	45.981	45.864	-0.1177
24	20	Biased	46.048	45.895	-0.1527
26	50	Biased	45.972	46.026	0.0539
27	30	Unbiased	45.897	45.922	0.0251
28	30	Biased	45.826	45.856	0.0294
29	30	Unbiased	45.857	45.826	-0.0309
30	20	Biased	45.952	46.042	0.0898
31	30	Unbiased	45.861	45.833	-0.0281
33	30	Biased	45.962	46.001	0.0389
34	50	Unbiased	46.117	46.17	0.053
35	20	Unbiased	45.883	45.931	0.0473
41	30	Biased	45.918	45.903	-0.0152

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	45.695	45.973	46.273	0.23661	45.686	45.922	46.205	0.21515	-0.1177	-0.05065	-0.008	0.052785
20	45.795	45.974	46.099	0.090759	45.812	45.979	46.163	0.1067	-0.1527	0.00471	0.1614	0.099558
30	45.798	45.895	46.011	0.067654	45.826	45.917	46.106	0.087679	-0.0309	0.02172	0.0951	0.042127
50	45.81	45.973	46.117	0.092628	45.882	46.004	46.17	0.095604	-0.0942	0.03083	0.0847	0.04918

Device Test: 27.40 LEVEL|WRST_MAX/OUT/14/14/0/0/5/200kHz//@MAX_DCL_50





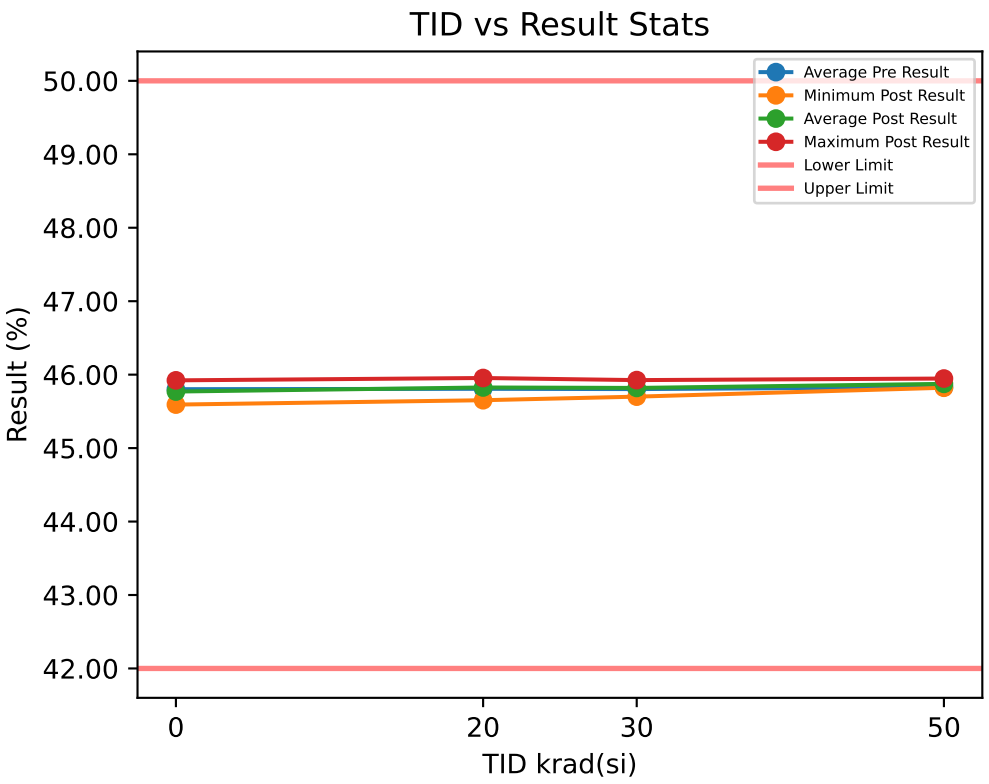
Test Results (Lower Limit = 42.0, Upper Limit = 50.0 (%))

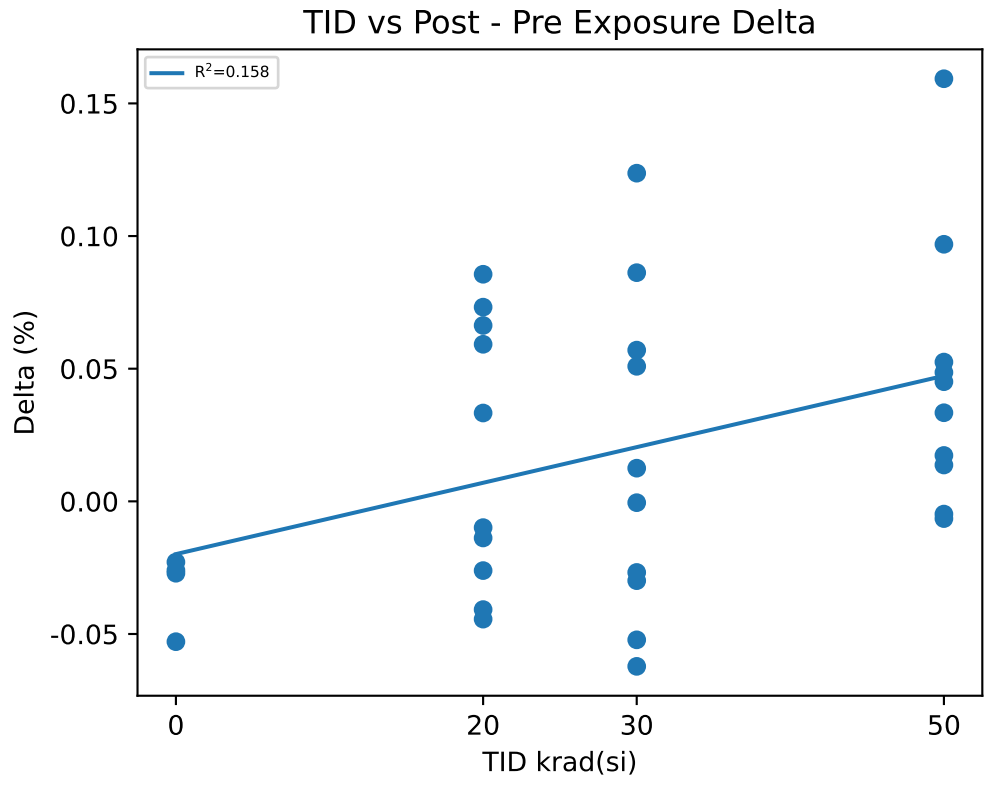
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	45.913	45.912	-0.0009
2	20	Unbiased	45.99	46.103	0.1132
3	50	Biased	45.966	46.08	0.1141
4	30	Unbiased	45.959	45.988	0.029
5	50	Unbiased	46.113	46.119	0.0066
6	30	Biased	46.017	46.111	0.0932
7	50	Biased	45.975	46.057	0.0816
8	30	Unbiased	45.794	45.851	0.0562
9	20	Unbiased	45.999	45.941	-0.058
10	50	Biased	45.799	45.863	0.064
11	30	Biased	45.837	45.87	0.0331
12	0	Correlation	45.953	45.891	-0.0619
13	0	Correlation	45.691	45.706	0.015
14	50	Unbiased	45.917	45.882	-0.0353
15	20	Biased	46.025	46.055	0.03
16	20	Unbiased	46.012	46.01	-0.0019
17	20	Biased	46.111	46.081	-0.0295
18	20	Unbiased	45.813	45.82	0.0064
19	20	Biased	45.848	45.836	-0.0115
20	50	Unbiased	46.039	45.953	-0.0853
21	0	Correlation	46.23	46.184	-0.0468
22	50	Unbiased	45.931	45.966	0.0348
23	0	Correlation	45.984	45.886	-0.0985
24	20	Biased	46.001	45.88	-0.121
26	50	Biased	45.925	46.01	0.085
27	30	Unbiased	45.931	45.935	0.0041
28	30	Biased	45.776	45.827	0.051
29	30	Unbiased	45.796	45.912	0.1165
30	20	Biased	45.93	46.045	0.1157
31	30	Unbiased	45.906	45.875	-0.0302
33	30	Biased	45.975	46.005	0.0292
34	50	Unbiased	46.101	46.171	0.0694
35	20	Unbiased	45.857	45.918	0.0612
41	30	Biased	45.924	45.927	0.0027

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	45.691	45.965	46.23	0.2206	45.706	45.917	46.184	0.19768	-0.0985	-0.04805	0.015	0.047307
20	45.813	45.959	46.111	0.093885	45.82	45.969	46.103	0.10368	-0.121	0.01046	0.1157	0.073639
30	45.776	45.892	46.017	0.084991	45.827	45.93	46.111	0.085157	-0.0302	0.03848	0.1165	0.04338
50	45.799	45.968	46.113	0.094957	45.863	46.001	46.171	0.10379	-0.0853	0.0334	0.1141	0.061857

Device Test: 27.41 LEVEL|WRST_MAX/OUT/4.5/4.5/0/0/4.5/500kHz//@MAX_DCL_50





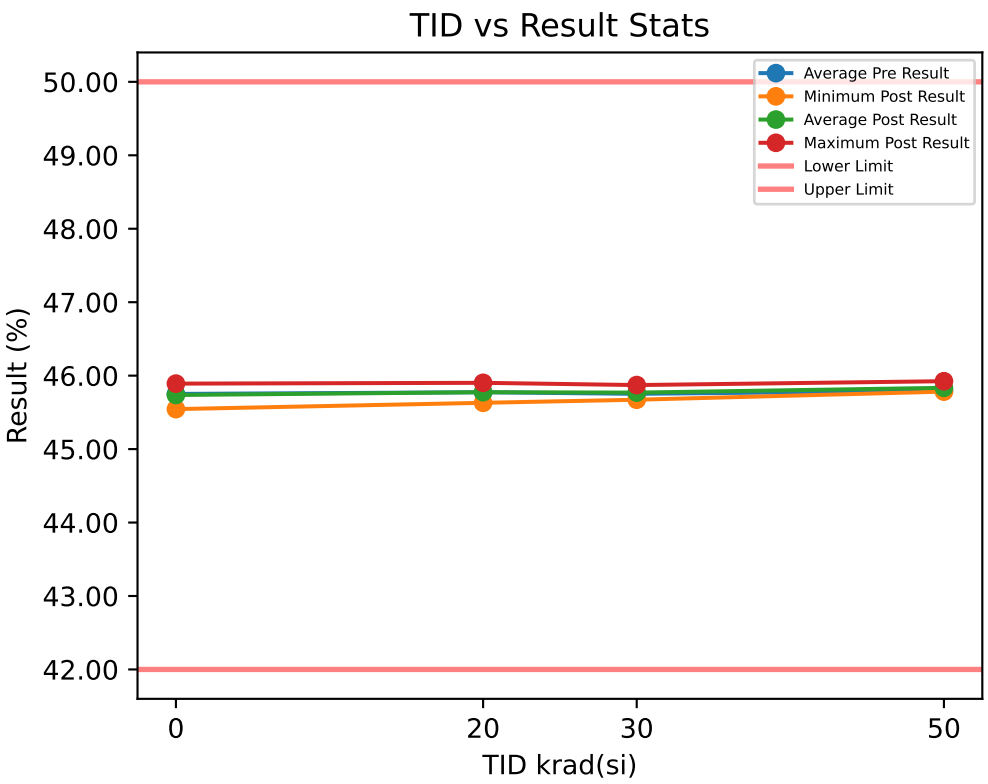
Test Results (Lower Limit = 42.0, Upper Limit = 50.0 (%))

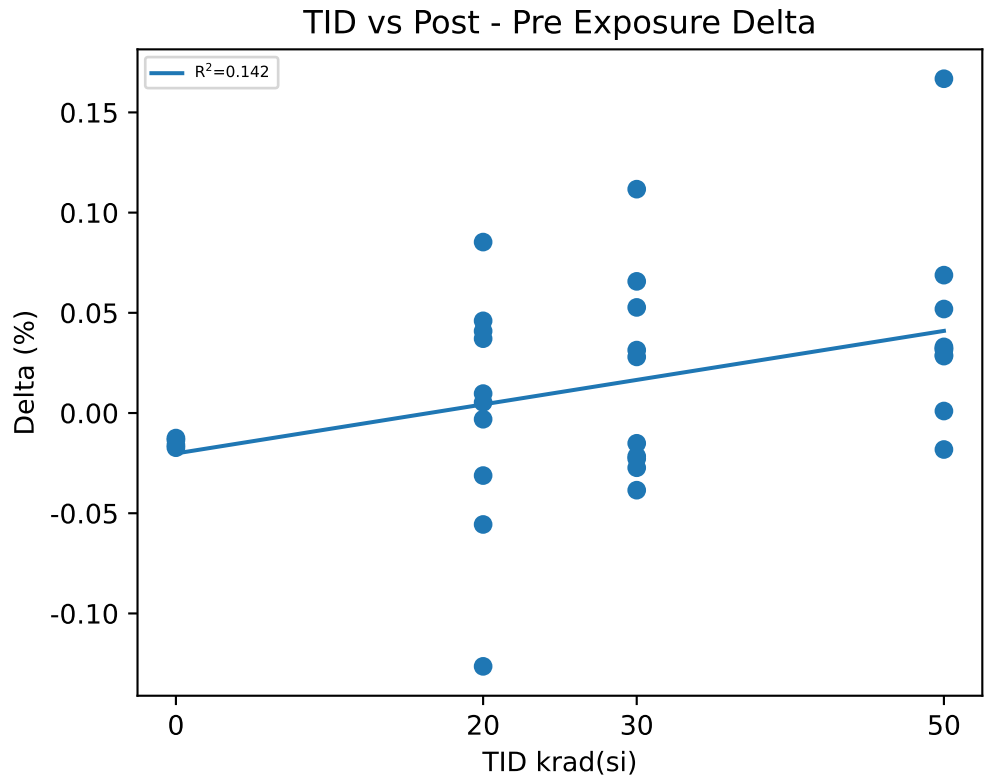
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	45.852	45.869	0.0173
2	20	Unbiased	45.888	45.954	0.0663
3	50	Biased	45.824	45.87	0.0451
4	30	Unbiased	45.873	45.885	0.0125
5	50	Unbiased	45.842	45.895	0.0525
6	30	Biased	45.869	45.926	0.057
7	50	Biased	45.883	45.877	-0.0065
8	30	Unbiased	45.785	45.758	-0.0268
9	20	Unbiased	45.79	45.849	0.0592
10	50	Biased	45.662	45.822	0.1593
11	30	Biased	45.772	45.822	0.0509
12	0	Correlation	45.82	45.793	-0.0271
13	0	Correlation	45.615	45.592	-0.0229
14	50	Unbiased	45.834	45.868	0.0334
15	20	Biased	45.861	45.895	0.0333
16	20	Unbiased	45.919	45.878	-0.0408
17	20	Biased	45.827	45.817	-0.0099
18	20	Unbiased	45.666	45.652	-0.0138
19	20	Biased	45.749	45.723	-0.0261
20	50	Unbiased	45.877	45.872	-0.0048
21	0	Correlation	45.948	45.922	-0.026
22	50	Unbiased	45.758	45.855	0.0969
23	0	Correlation	45.825	45.772	-0.0529
24	20	Biased	45.831	45.786	-0.0444
26	50	Biased	45.824	45.873	0.0486
27	30	Unbiased	45.864	45.834	-0.0299
28	30	Biased	45.763	45.7	-0.0622
29	30	Unbiased	45.735	45.735	-0.0005
30	20	Biased	45.768	45.853	0.0856
31	30	Unbiased	45.8	45.748	-0.0522
33	30	Biased	45.838	45.924	0.0862
34	50	Unbiased	45.933	45.947	0.0137
35	20	Unbiased	45.773	45.846	0.0732
41	30	Biased	45.736	45.86	0.1237

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	45.615	45.802	45.948	0.13799	45.592	45.77	45.922	0.13576	-0.0529	-0.032225	-0.0229	0.013898
20	45.666	45.807	45.919	0.074034	45.652	45.825	45.954	0.087053	-0.0444	0.01826	0.0856	0.050515
30	45.735	45.803	45.873	0.053885	45.7	45.819	45.926	0.080767	-0.0622	0.01587	0.1237	0.061838
50	45.662	45.829	45.933	0.074373	45.822	45.875	45.947	0.031563	-0.0065	0.04555	0.1593	0.050374

Device Test: 27.42 LEVEL|WRST_MAX/OUT/5/5/0/0/5/500kHz//@MAX_DCL_50





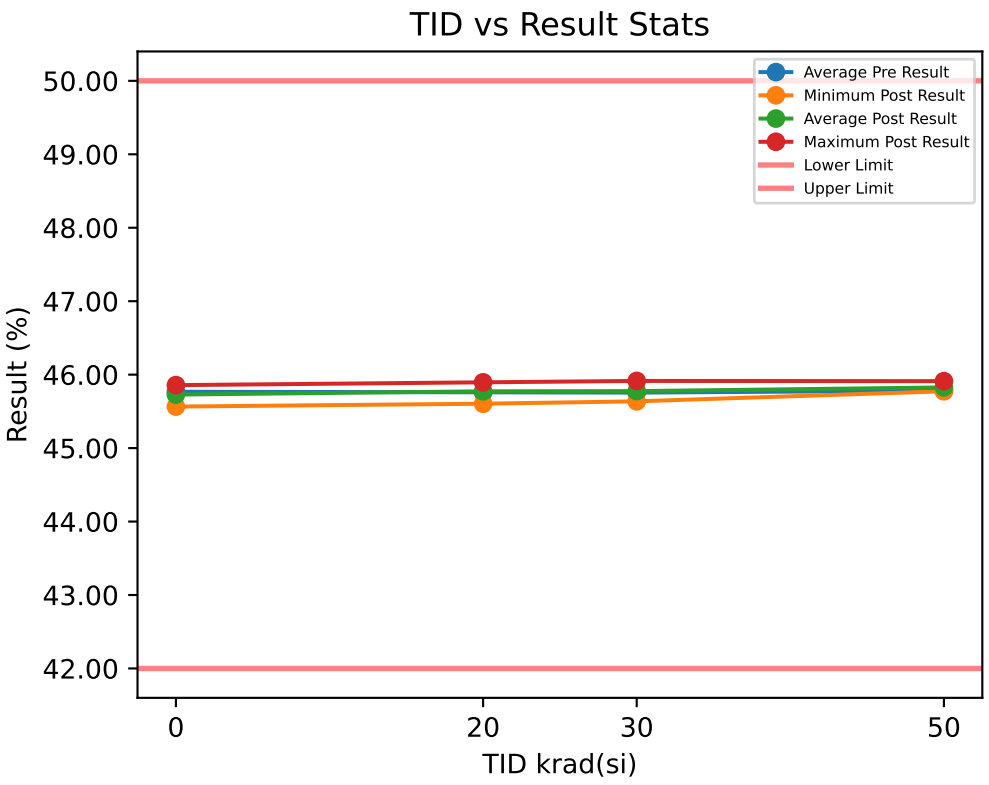
Test Results (Lower Limit = 42.0, Upper Limit = 50.0 (%))

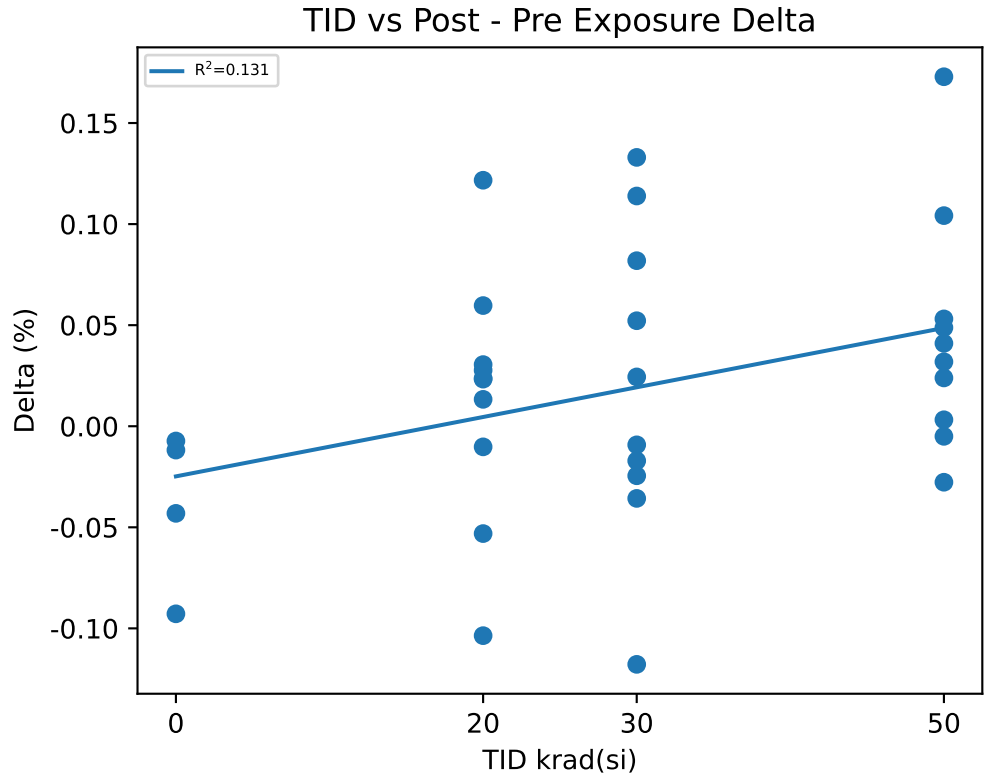
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	45.792	45.821	0.0289
2	20	Unbiased	45.856	45.902	0.046
3	50	Biased	45.773	45.804	0.0316
4	30	Unbiased	45.848	45.833	-0.0151
5	50	Unbiased	45.831	45.859	0.0284
6	30	Biased	45.84	45.872	0.0314
7	50	Biased	45.835	45.836	0.001
8	30	Unbiased	45.742	45.714	-0.0273
9	20	Unbiased	45.785	45.79	0.0053
10	50	Biased	45.616	45.783	0.1668
11	30	Biased	45.693	45.745	0.0527
12	0	Correlation	45.788	45.775	-0.0135
13	0	Correlation	45.562	45.544	-0.0173
14	50	Unbiased	45.788	45.857	0.0688
15	20	Biased	45.883	45.852	-0.0312
16	20	Unbiased	45.871	45.815	-0.0556
17	20	Biased	45.796	45.805	0.0097
18	20	Unbiased	45.593	45.63	0.0371
19	20	Biased	45.654	45.651	-0.0031
20	50	Unbiased	45.847	45.829	-0.0182
21	0	Correlation	45.904	45.892	-0.0125
22	50	Unbiased	45.749	45.8	0.0519
23	0	Correlation	45.751	45.735	-0.016
24	20	Biased	45.852	45.725	-0.1264
26	50	Biased	45.797	45.83	0.033
27	30	Unbiased	45.776	45.804	0.028
28	30	Biased	45.694	45.672	-0.0216
29	30	Unbiased	45.711	45.688	-0.0228
30	20	Biased	45.732	45.773	0.0409
31	30	Unbiased	45.721	45.683	-0.0385
33	30	Biased	45.796	45.861	0.0657
34	50	Unbiased	45.892	45.924	0.0322
35	20	Unbiased	45.718	45.803	0.0853
41	30	Biased	45.707	45.818	0.1117

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	45.562	45.751	45.904	0.1421	45.544	45.736	45.892	0.14415	-0.0173	-0.014825	-0.0125	0.0022111
20	45.593	45.774	45.883	0.098206	45.63	45.775	45.902	0.084725	-0.1264	0.0008	0.0853	0.060193
30	45.693	45.753	45.848	0.058843	45.672	45.769	45.872	0.077246	-0.0385	0.01642	0.1117	0.049538
50	45.616	45.792	45.892	0.07436	45.783	45.834	45.924	0.039682	-0.0182	0.04244	0.1668	0.049818

Device Test: 27.43 LEVEL|WRST_MAX/OUT/12/12/0/0/5/500kHz//@MAX_DCL_50





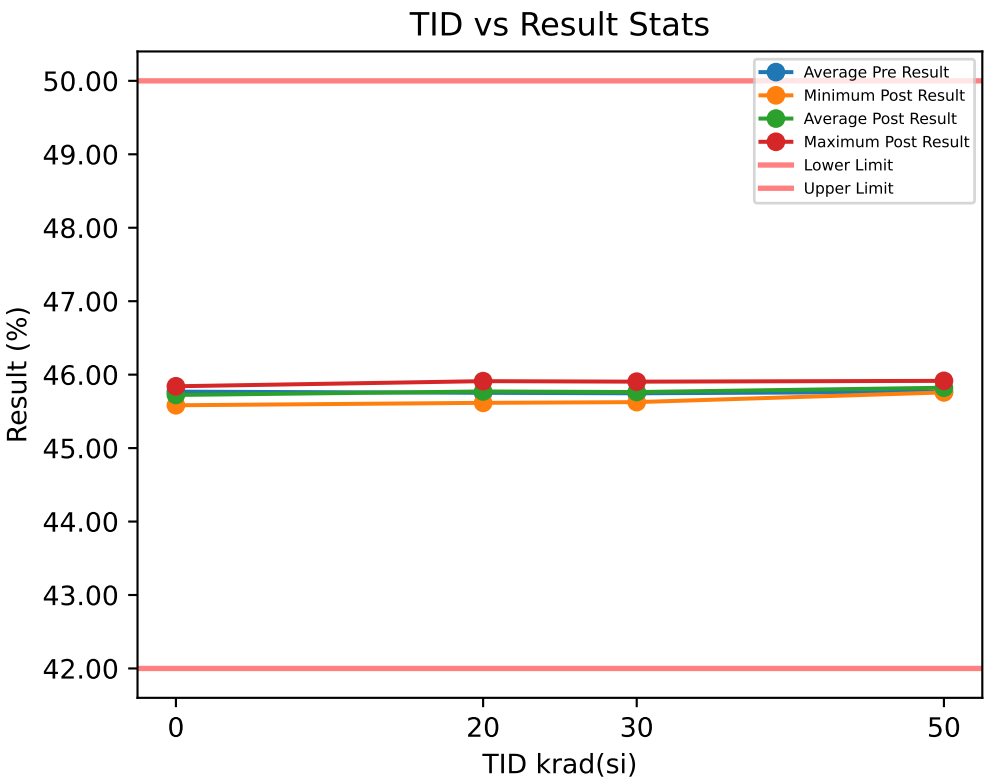
Test Results (Lower Limit = 42.0, Upper Limit = 50.0 (%))

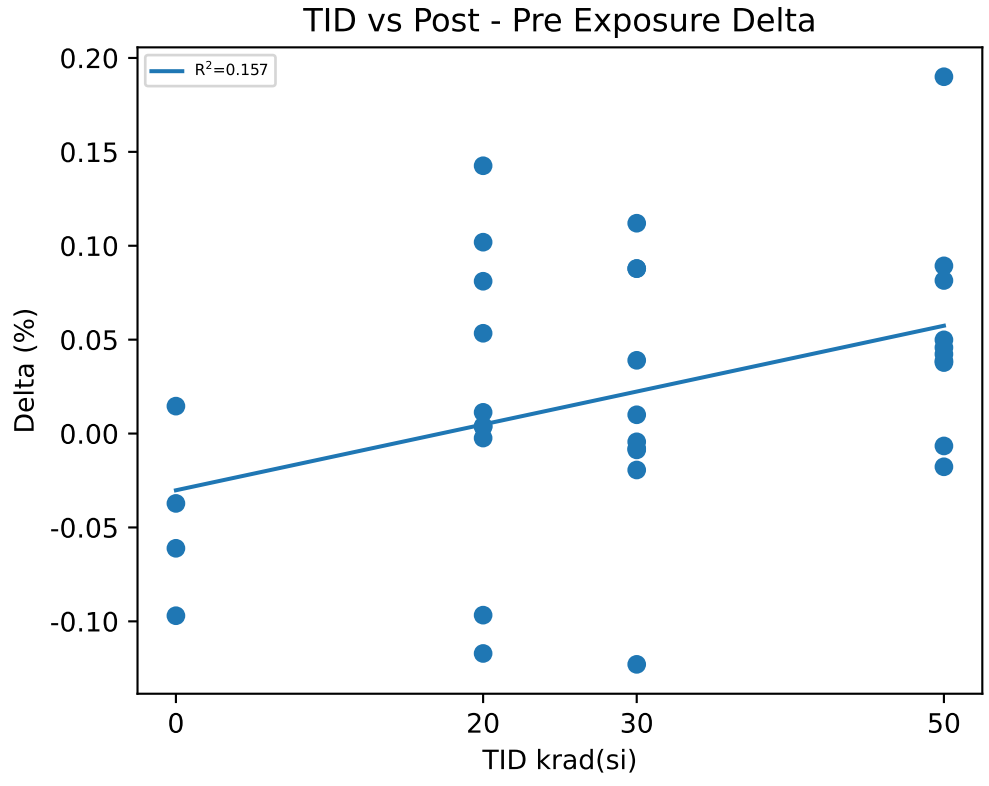
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	45.804	45.807	0.0032
2	20	Unbiased	45.836	45.896	0.0597
3	50	Biased	45.785	45.808	0.0239
4	30	Unbiased	45.861	45.837	-0.0245
5	50	Unbiased	45.825	45.866	0.041
6	30	Biased	45.781	45.914	0.133
7	50	Biased	45.855	45.85	-0.005
8	30	Unbiased	45.753	45.717	-0.0357
9	20	Unbiased	45.761	45.774	0.0133
10	50	Biased	45.6	45.773	0.1729
11	30	Biased	45.744	45.796	0.0522
12	0	Correlation	45.801	45.789	-0.0118
13	0	Correlation	45.573	45.565	-0.0073
14	50	Unbiased	45.777	45.826	0.0488
15	20	Biased	45.862	45.89	0.0277
16	20	Unbiased	45.863	45.81	-0.0531
17	20	Biased	45.788	45.778	-0.0102
18	20	Unbiased	45.581	45.605	0.0233
19	20	Biased	45.657	45.681	0.0237
20	50	Unbiased	45.838	45.81	-0.0277
21	0	Correlation	45.9	45.857	-0.0431
22	50	Unbiased	45.687	45.791	0.1042
23	0	Correlation	45.796	45.703	-0.0928
24	20	Biased	45.831	45.728	-0.1036
26	50	Biased	45.763	45.816	0.0531
27	30	Unbiased	45.8	45.783	-0.0171
28	30	Biased	45.666	45.657	-0.0092
29	30	Unbiased	45.689	45.713	0.0244
30	20	Biased	45.677	45.798	0.1217
31	30	Unbiased	45.755	45.637	-0.1178
33	30	Biased	45.817	45.898	0.0819
34	50	Unbiased	45.88	45.911	0.0319
35	20	Unbiased	45.739	45.769	0.0305
41	30	Biased	45.692	45.806	0.1139

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	45.573	45.767	45.9	0.13851	45.565	45.729	45.857	0.12591	-0.0928	-0.03875	-0.0073	0.039394
20	45.581	45.76	45.863	0.095838	45.605	45.773	45.896	0.087973	-0.1036	0.0133	0.1217	0.060774
30	45.666	45.756	45.861	0.061692	45.637	45.776	45.914	0.094429	-0.1178	0.02011	0.133	0.076576
50	45.6	45.781	45.88	0.08347	45.773	45.826	45.911	0.04012	-0.0277	0.04463	0.1729	0.057838

Device Test: 27.44 LEVEL|WRST_MAX/OUT/14/14/0/0/5/500kHz//@MAX_DCL_50





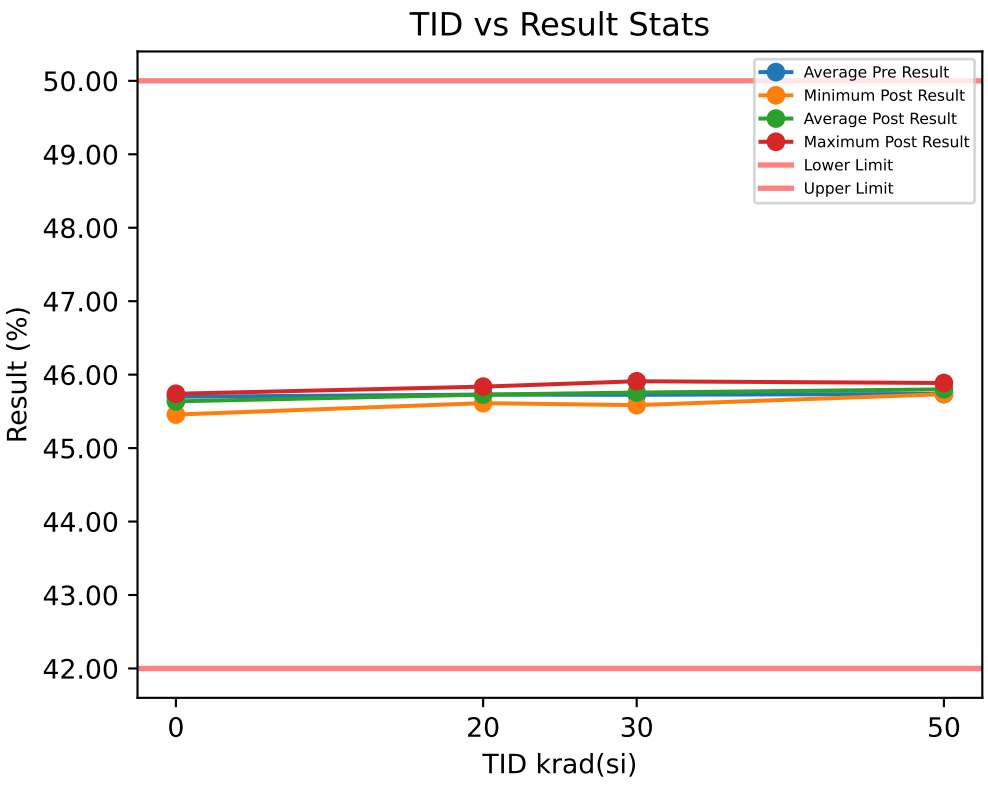
Test Results (Lower Limit = 42.0, Upper Limit = 50.0 (%))

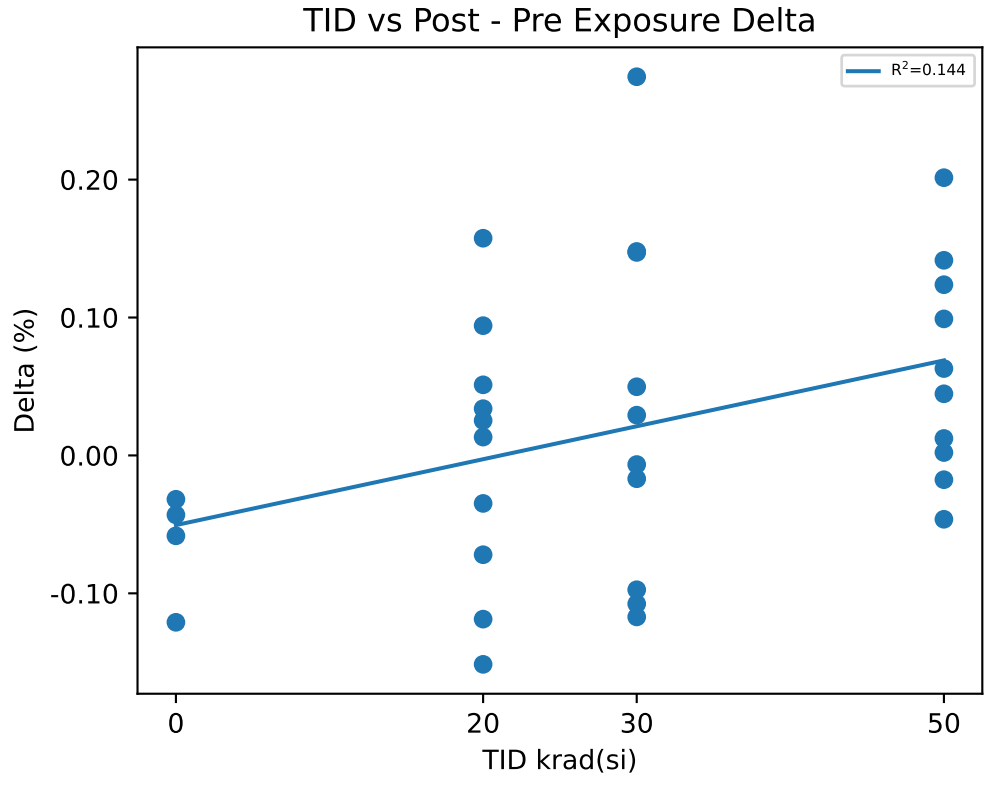
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	45.785	45.835	0.0499
2	20	Unbiased	45.809	45.911	0.1019
3	50	Biased	45.8	45.838	0.0387
4	30	Unbiased	45.828	45.819	-0.0087
5	50	Unbiased	45.798	45.887	0.0893
6	30	Biased	45.792	45.904	0.112
7	50	Biased	45.849	45.842	-0.0066
8	30	Unbiased	45.72	45.7	-0.0194
9	20	Unbiased	45.769	45.766	-0.0024
10	50	Biased	45.588	45.778	0.19
11	30	Biased	45.775	45.77	-0.0044
12	0	Correlation	45.811	45.774	-0.0372
13	0	Correlation	45.568	45.583	0.0146
14	50	Unbiased	45.744	45.79	0.0458
15	20	Biased	45.868	45.872	0.004
16	20	Unbiased	45.894	45.777	-0.1171
17	20	Biased	45.778	45.781	0.0036
18	20	Unbiased	45.563	45.616	0.0534
19	20	Biased	45.688	45.699	0.0113
20	50	Unbiased	45.811	45.793	-0.0177
21	0	Correlation	45.903	45.842	-0.0611
22	50	Unbiased	45.677	45.758	0.0815
23	0	Correlation	45.792	45.695	-0.097
24	20	Biased	45.804	45.707	-0.0967
26	50	Biased	45.741	45.779	0.0378
27	30	Unbiased	45.745	45.784	0.039
28	30	Biased	45.65	45.642	-0.0079
29	30	Unbiased	45.682	45.692	0.01
30	20	Biased	45.64	45.783	0.1426
31	30	Unbiased	45.749	45.626	-0.1229
33	30	Biased	45.81	45.898	0.0878
34	50	Unbiased	45.873	45.916	0.0423
35	20	Unbiased	45.718	45.799	0.0811
41	30	Biased	45.71	45.798	0.0879

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	45.568	45.769	45.903	0.14189	45.583	45.723	45.842	0.11109	-0.097	-0.045175	0.0146	0.046819
20	45.563	45.753	45.894	0.10228	45.616	45.771	45.911	0.084501	-0.1171	0.01817	0.1426	0.081698
30	45.65	45.746	45.828	0.056972	45.626	45.763	45.904	0.097489	-0.1229	0.01734	0.112	0.068501
50	45.588	45.767	45.873	0.084134	45.758	45.822	45.916	0.051192	-0.0177	0.0551	0.19	0.057751

Device Test: 27.45 LEVEL|WRST_MAX/OUT/4.5/4.5/0/0/4.5/1MHz//@MAX_DCL_50





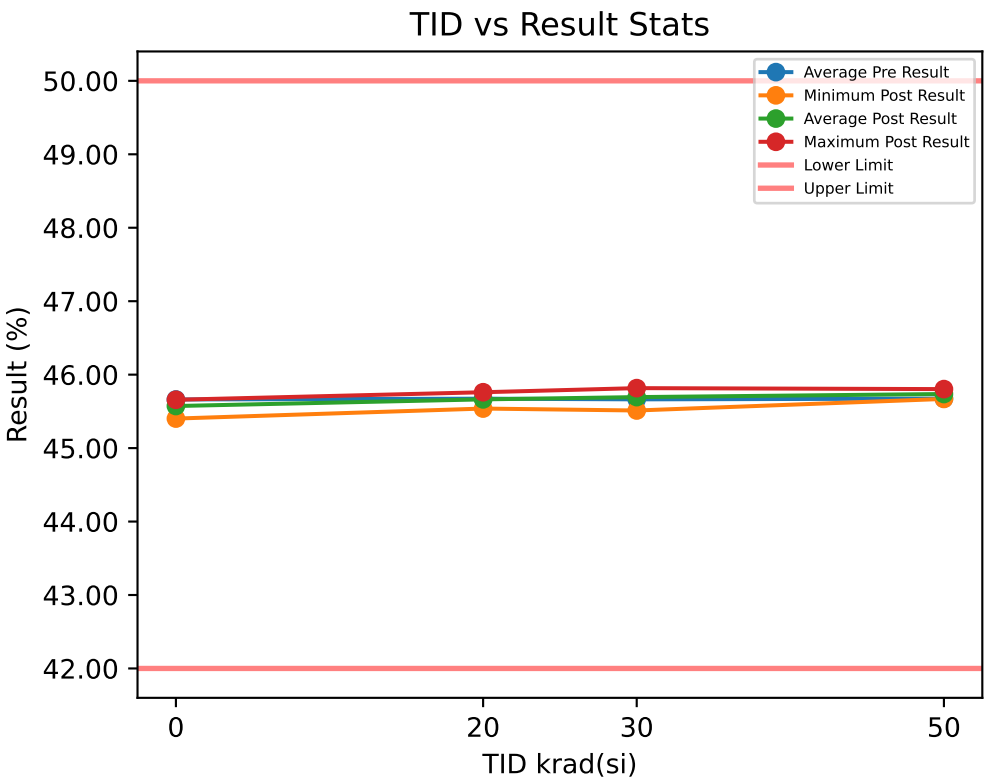
Test Results (Lower Limit = 42.0, Upper Limit = 50.0 (%))

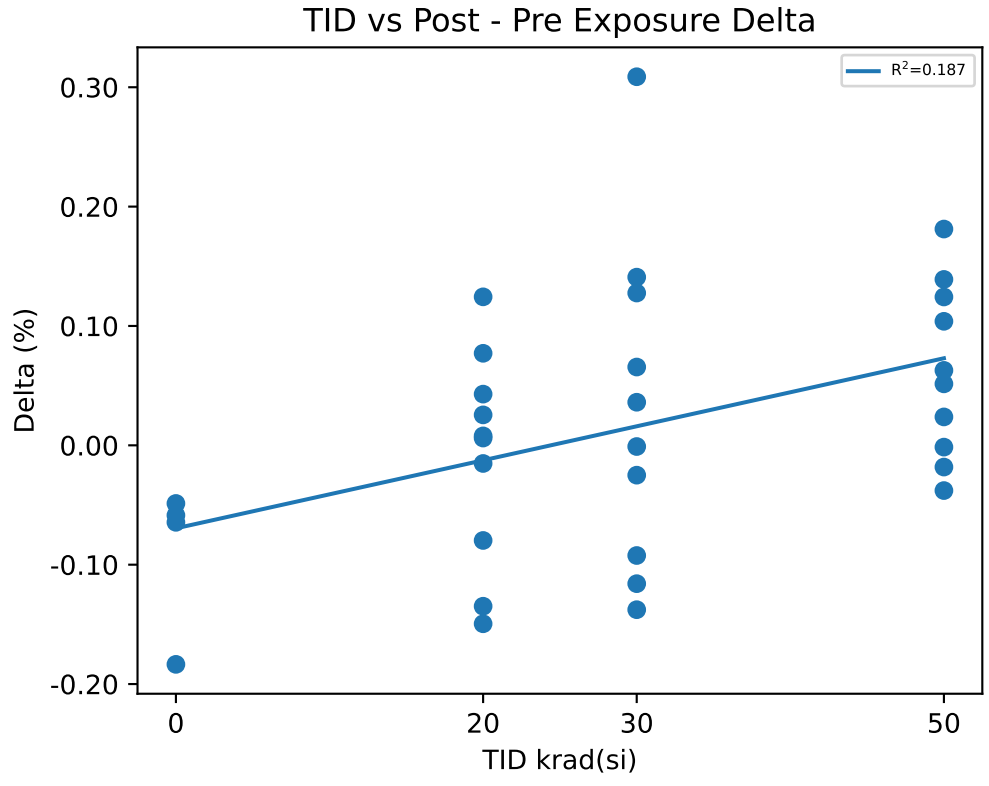
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	45.786	45.798	0.0123
2	20	Unbiased	45.761	45.774	0.0133
3	50	Biased	45.754	45.757	0.0021
4	30	Unbiased	45.869	45.862	-0.0066
5	50	Unbiased	45.763	45.886	0.1238
6	30	Biased	45.762	45.91	0.1479
7	50	Biased	45.8	45.754	-0.0463
8	30	Unbiased	45.734	45.617	-0.1171
9	20	Unbiased	45.729	45.823	0.0941
10	50	Biased	45.632	45.833	0.2014
11	30	Biased	45.706	45.756	0.0498
12	0	Correlation	45.771	45.74	-0.0318
13	0	Correlation	45.515	45.456	-0.0583
14	50	Unbiased	45.719	45.818	0.099
15	20	Biased	45.812	45.837	0.0253
16	20	Unbiased	45.804	45.686	-0.1187
17	20	Biased	45.723	45.688	-0.0348
18	20	Unbiased	45.578	45.612	0.0339
19	20	Biased	45.703	45.631	-0.072
20	50	Unbiased	45.8	45.783	-0.0176
21	0	Correlation	45.759	45.715	-0.0431
22	50	Unbiased	45.674	45.815	0.1415
23	0	Correlation	45.753	45.632	-0.121
24	20	Biased	45.793	45.641	-0.1515
26	50	Biased	45.671	45.734	0.063
27	30	Unbiased	45.763	45.792	0.0292
28	30	Biased	45.733	45.636	-0.0974
29	30	Unbiased	45.686	45.669	-0.0169
30	20	Biased	45.642	45.8	0.1575
31	30	Unbiased	45.692	45.585	-0.1076
33	30	Biased	45.751	45.898	0.1472
34	50	Unbiased	45.773	45.818	0.0447
35	20	Unbiased	45.737	45.788	0.0512
41	30	Biased	45.56	45.834	0.2746

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	45.515	45.699	45.771	0.12342	45.456	45.636	45.74	0.12822	-0.121	-0.06355	-0.0318	0.039809
20	45.578	45.728	45.812	0.073521	45.612	45.728	45.837	0.085291	-0.1515	-0.00017	0.1575	0.095269
30	45.56	45.726	45.869	0.077867	45.585	45.756	45.91	0.1216	-0.1171	0.03031	0.2746	0.12832
50	45.632	45.737	45.8	0.060026	45.734	45.8	45.886	0.044859	-0.0463	0.06239	0.2014	0.078431

Device Test: 27.46 LEVEL|WRST_MAX/OUT/5/5/0/0/5/1MHz//@MAX_DCL_50





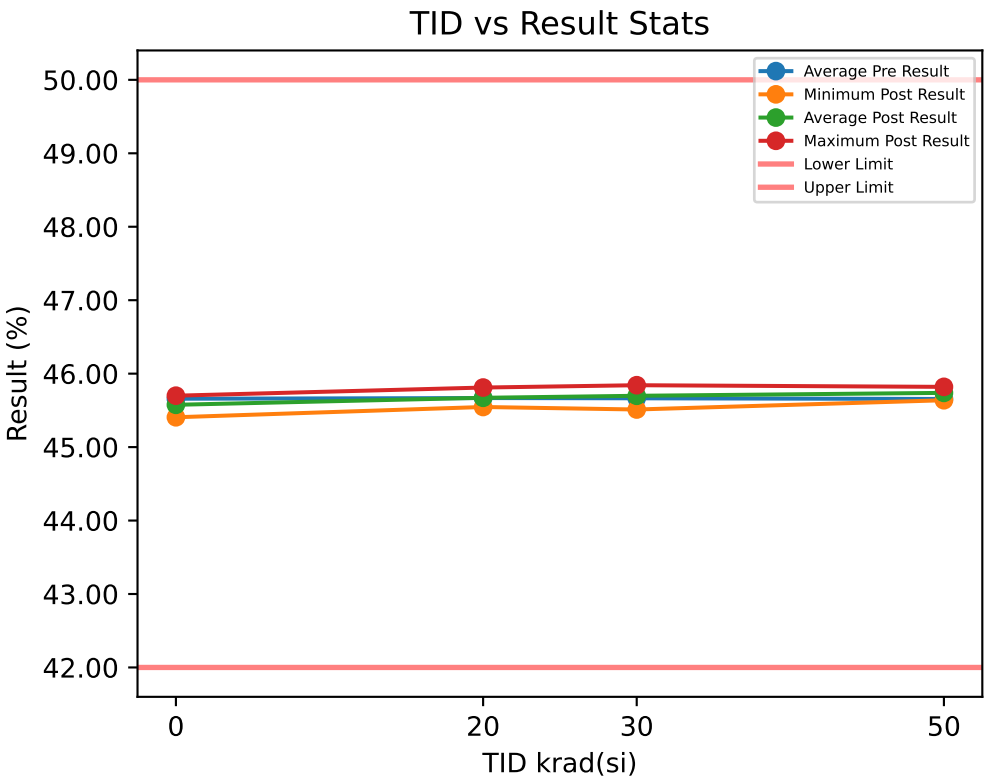
Test Results (Lower Limit = 42.0, Upper Limit = 50.0 (%))

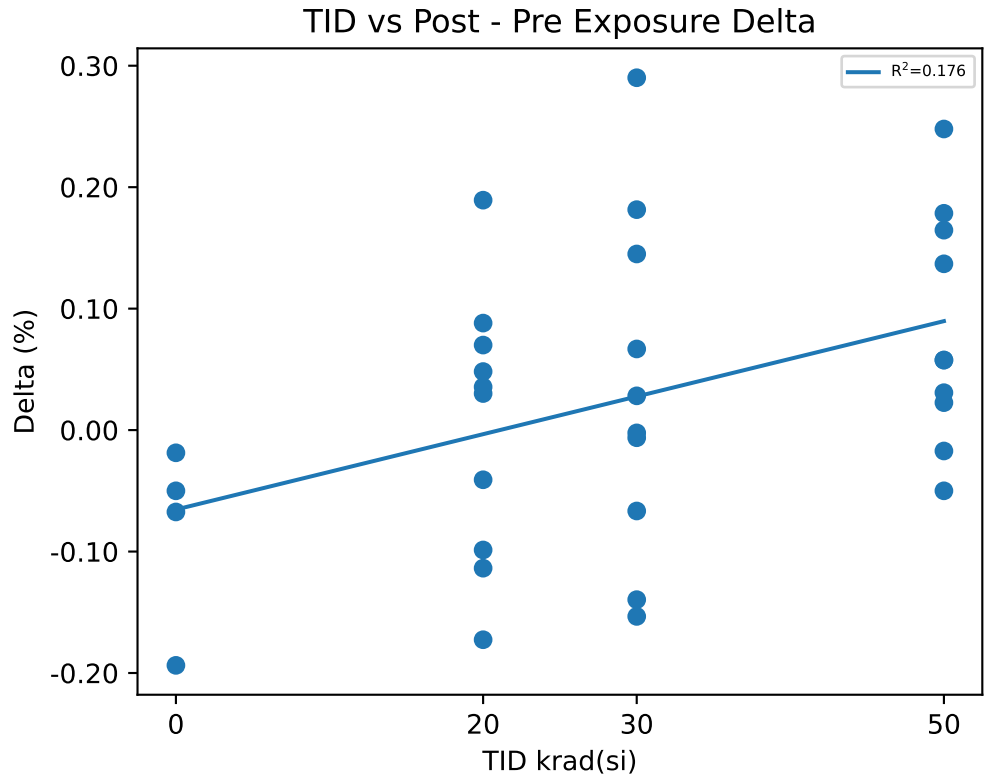
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	45.694	45.718	0.0238
2	20	Unbiased	45.688	45.714	0.0255
3	50	Biased	45.704	45.686	-0.0182
4	30	Unbiased	45.787	45.786	-0.001
5	50	Unbiased	45.679	45.803	0.1243
6	30	Biased	45.689	45.816	0.1276
7	50	Biased	45.727	45.69	-0.0379
8	30	Unbiased	45.711	45.595	-0.1159
9	20	Unbiased	45.676	45.753	0.0771
10	50	Biased	45.587	45.768	0.1812
11	30	Biased	45.657	45.722	0.0656
12	0	Correlation	45.707	45.658	-0.0487
13	0	Correlation	45.461	45.402	-0.0586
14	50	Unbiased	45.665	45.769	0.1039
15	20	Biased	45.754	45.761	0.0061
16	20	Unbiased	45.761	45.611	-0.1495
17	20	Biased	45.658	45.643	-0.0152
18	20	Unbiased	45.531	45.538	0.0079
19	20	Biased	45.646	45.567	-0.0797
20	50	Unbiased	45.75	45.748	-0.0015
21	0	Correlation	45.717	45.653	-0.0645
22	50	Unbiased	45.618	45.757	0.139
23	0	Correlation	45.762	45.579	-0.1835
24	20	Biased	45.724	45.589	-0.1348
26	50	Biased	45.607	45.669	0.0628
27	30	Unbiased	45.698	45.734	0.0361
28	30	Biased	45.662	45.57	-0.0923
29	30	Unbiased	45.617	45.592	-0.025
30	20	Biased	45.618	45.743	0.1244
31	30	Unbiased	45.65	45.512	-0.1377
33	30	Biased	45.675	45.816	0.1409
34	50	Unbiased	45.703	45.755	0.0515
35	20	Unbiased	45.672	45.715	0.0429
41	30	Biased	45.49	45.799	0.3088

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	45.461	45.662	45.762	0.13623	45.402	45.573	45.658	0.11954	-0.1835	-0.088825	-0.0487	0.063452
20	45.531	45.673	45.761	0.067777	45.538	45.663	45.761	0.083401	-0.1495	-0.00953	0.1244	0.088322
30	45.49	45.664	45.787	0.075992	45.512	45.694	45.816	0.11564	-0.1377	0.03071	0.3088	0.13712
50	45.587	45.673	45.75	0.053943	45.669	45.736	45.803	0.043415	-0.0379	0.06289	0.1812	0.072863

Device Test: 27.47 LEVEL|WRST_MAX/OUT/12/12/0/0/5/1MHz//@MAX_DCL_50





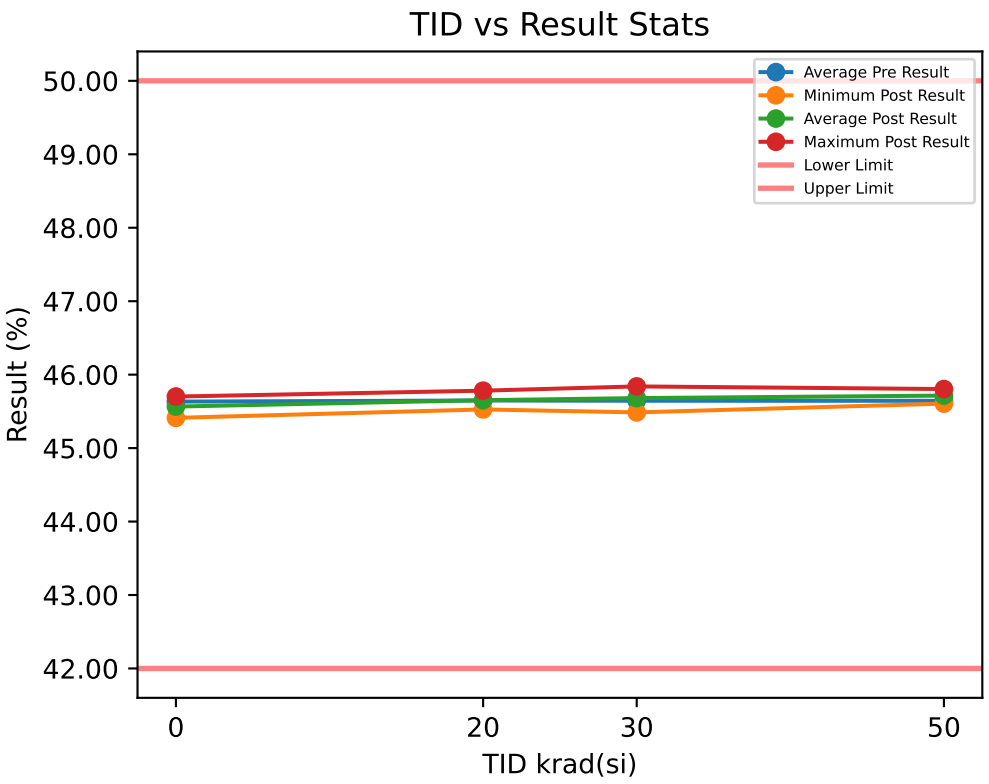
Test Results (Lower Limit = 42.0, Upper Limit = 50.0 (%))

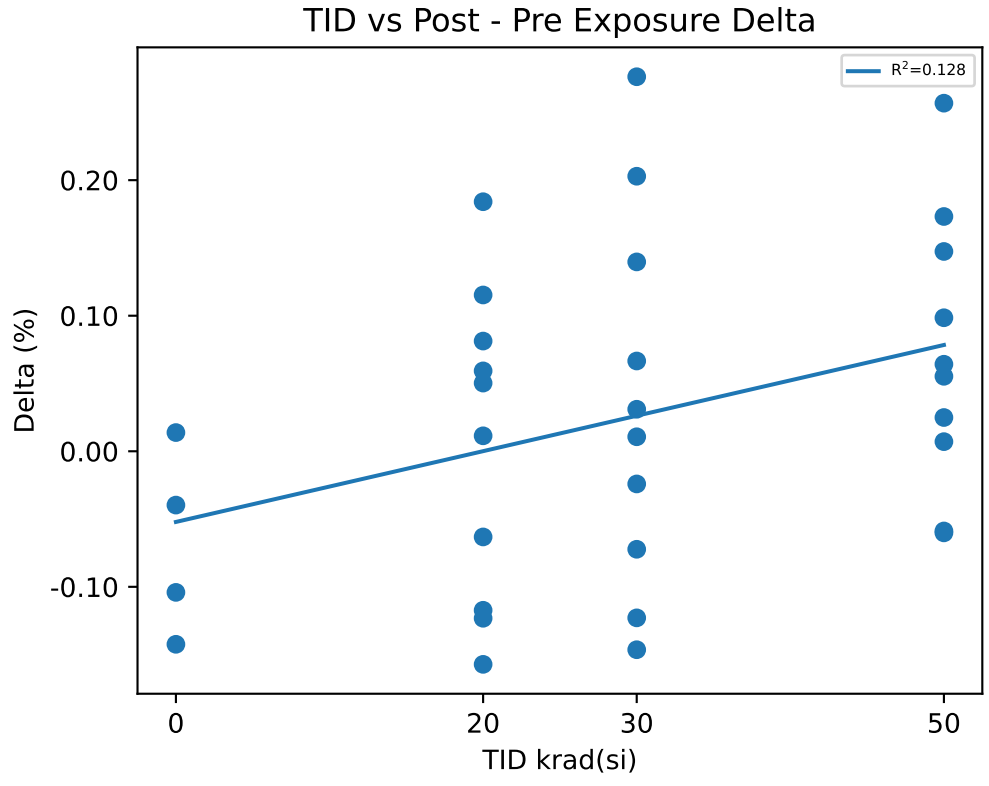
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	45.691	45.722	0.0308
2	20	Unbiased	45.671	45.719	0.0482
3	50	Biased	45.724	45.707	-0.0172
4	30	Unbiased	45.794	45.788	-0.0063
5	50	Unbiased	45.683	45.82	0.1369
6	30	Biased	45.661	45.843	0.1815
7	50	Biased	45.73	45.68	-0.05
8	30	Unbiased	45.698	45.545	-0.1534
9	20	Unbiased	45.678	45.766	0.0881
10	50	Biased	45.562	45.81	0.2479
11	30	Biased	45.66	45.727	0.0668
12	0	Correlation	45.719	45.7	-0.0187
13	0	Correlation	45.474	45.406	-0.0674
14	50	Unbiased	45.616	45.781	0.1646
15	20	Biased	45.775	45.811	0.0355
16	20	Unbiased	45.731	45.617	-0.1137
17	20	Biased	45.667	45.626	-0.0409
18	20	Unbiased	45.495	45.565	0.07
19	20	Biased	45.688	45.589	-0.0987
20	50	Unbiased	45.725	45.747	0.0226
21	0	Correlation	45.684	45.634	-0.05
22	50	Unbiased	45.56	45.739	0.1785
23	0	Correlation	45.757	45.563	-0.1937
24	20	Biased	45.719	45.546	-0.1726
26	50	Biased	45.58	45.638	0.0577
27	30	Unbiased	45.716	45.745	0.0282
28	30	Biased	45.647	45.58	-0.0666
29	30	Unbiased	45.615	45.612	-0.0023
30	20	Biased	45.553	45.742	0.1893
31	30	Unbiased	45.651	45.512	-0.1396
33	30	Biased	45.694	45.839	0.145
34	50	Unbiased	45.68	45.738	0.0576
35	20	Unbiased	45.702	45.733	0.0301
41	30	Biased	45.507	45.797	0.2901

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	45.474	45.658	45.757	0.12674	45.406	45.576	45.7	0.12622	-0.1937	-0.08245	-0.0187	0.076855
20	45.495	45.668	45.775	0.083618	45.546	45.671	45.811	0.09319	-0.1726	0.00353	0.1893	0.10903
30	45.507	45.664	45.794	0.074051	45.512	45.699	45.843	0.12512	-0.1534	0.03434	0.2901	0.14106
50	45.56	45.655	45.73	0.068885	45.638	45.738	45.82	0.056215	-0.05	0.08294	0.2479	0.095022

Device Test: 27.48 LEVEL|WRST_MAX/OUT/14/14/0/0/5/1MHz//@MAX_DCL_50





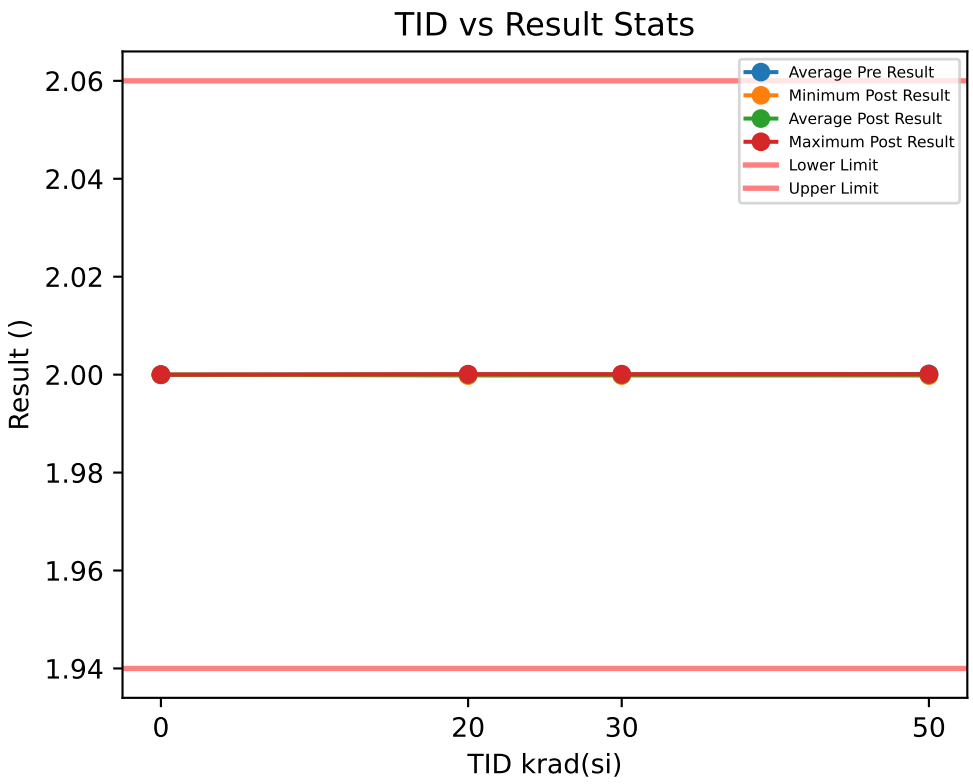
Test Results (Lower Limit = 42.0, Upper Limit = 50.0 (%))

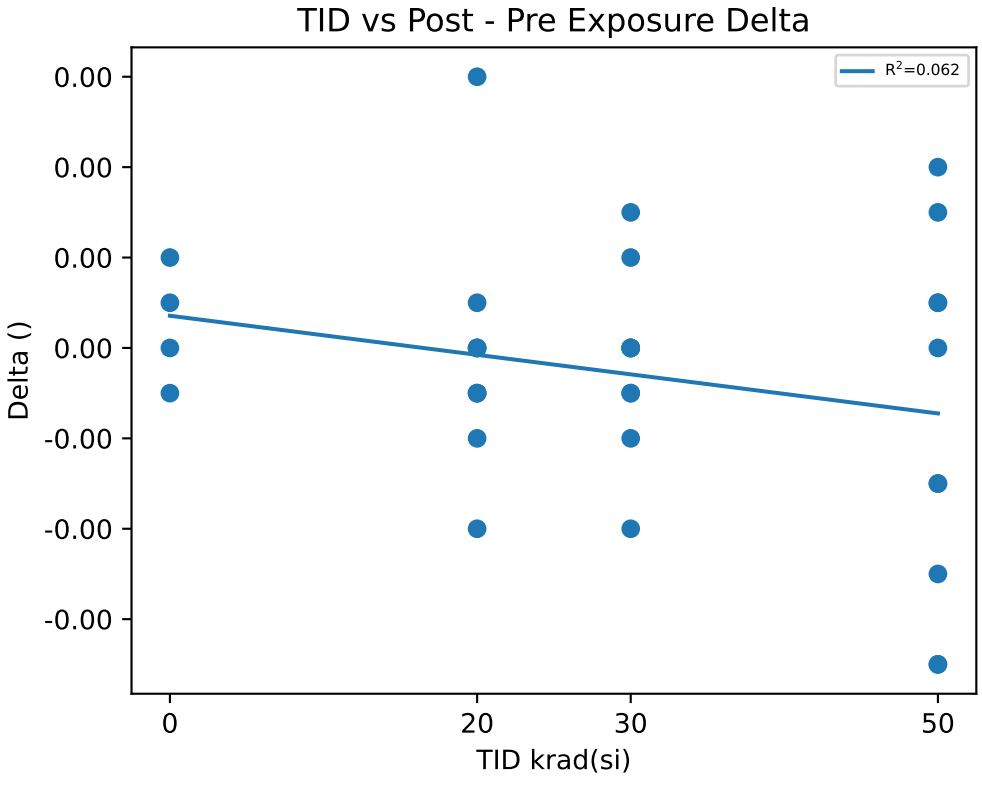
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	45.684	45.709	0.0249
2	20	Unbiased	45.624	45.74	0.1153
3	50	Biased	45.731	45.672	-0.0588
4	30	Unbiased	45.767	45.742	-0.0241
5	50	Unbiased	45.657	45.804	0.1474
6	30	Biased	45.637	45.84	0.2029
7	50	Biased	45.714	45.654	-0.0602
8	30	Unbiased	45.659	45.536	-0.1229
9	20	Unbiased	45.645	45.727	0.0813
10	50	Biased	45.524	45.781	0.2568
11	30	Biased	45.64	45.706	0.0666
12	0	Correlation	45.688	45.702	0.0138
13	0	Correlation	45.451	45.412	-0.0397
14	50	Unbiased	45.645	45.743	0.0985
15	20	Biased	45.77	45.782	0.0114
16	20	Unbiased	45.738	45.581	-0.1572
17	20	Biased	45.664	45.601	-0.0632
18	20	Unbiased	45.467	45.526	0.0593
19	20	Biased	45.669	45.552	-0.1173
20	50	Unbiased	45.701	45.708	0.0071
21	0	Correlation	45.687	45.582	-0.1041
22	50	Unbiased	45.563	45.736	0.1732
23	0	Correlation	45.707	45.565	-0.1424
24	20	Biased	45.688	45.565	-0.1232
26	50	Biased	45.55	45.605	0.0553
27	30	Unbiased	45.704	45.715	0.0107
28	30	Biased	45.632	45.559	-0.0723
29	30	Unbiased	45.598	45.629	0.031
30	20	Biased	45.543	45.727	0.1841
31	30	Unbiased	45.633	45.486	-0.1464
33	30	Biased	45.685	45.825	0.1397
34	50	Unbiased	45.671	45.735	0.0642
35	20	Unbiased	45.673	45.723	0.0503
41	30	Biased	45.492	45.768	0.2763

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	45.451	45.633	45.707	0.12156	45.412	45.565	45.702	0.11905	-0.1424	-0.0681	0.0138	0.069115
20	45.467	45.648	45.77	0.088358	45.526	45.652	45.782	0.095384	-0.1572	0.00408	0.1841	0.11424
30	45.492	45.645	45.767	0.071599	45.486	45.681	45.84	0.12281	-0.1464	0.03615	0.2763	0.13817
50	45.524	45.644	45.731	0.073118	45.605	45.715	45.804	0.059163	-0.0602	0.07084	0.2568	0.10117

Device Test: 28.1 LEVEL|RATIO/CS/4.5/4.5/0/0/4.5/500kHz//@C_CS_R





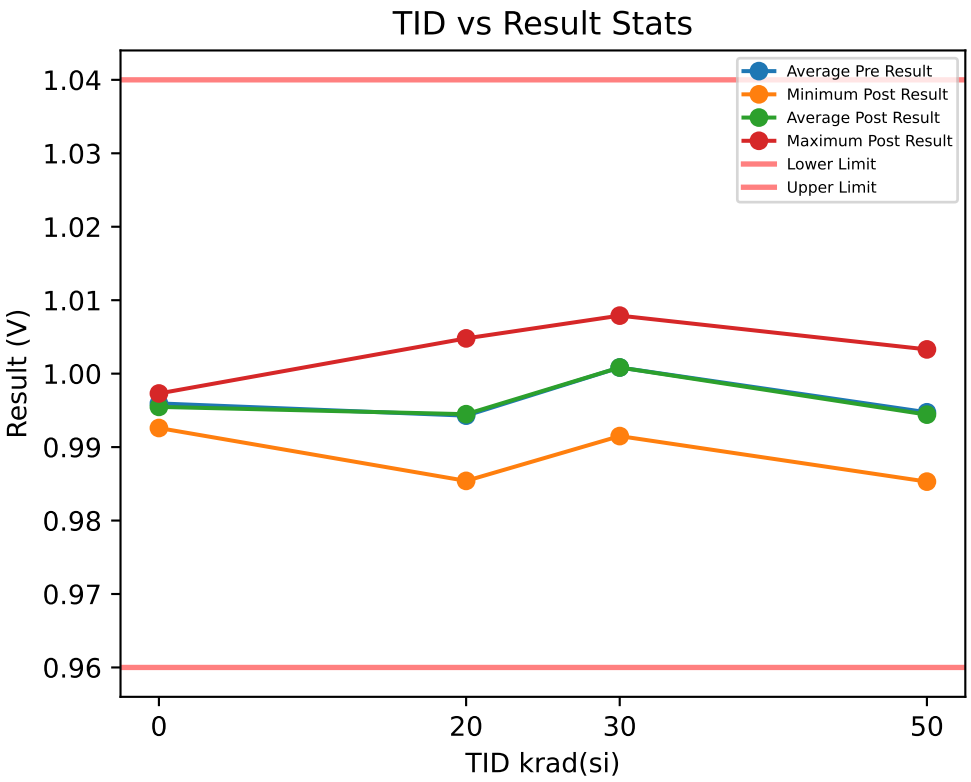
Test Results (Lower Limit = 1.94, Upper Limit = 2.06 ())

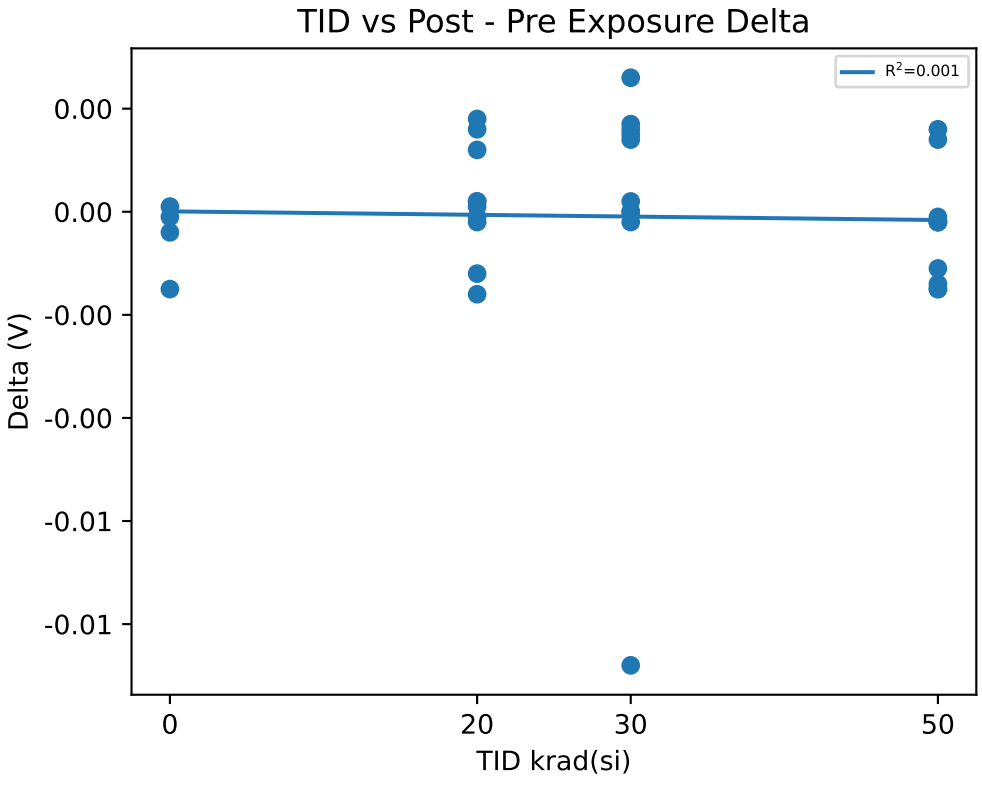
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	2	2	0
2	20	Unbiased	2	2	0
3	50	Biased	1.9997	2.0001	0.0004
4	30	Unbiased	2.0001	2	-0.0001
5	50	Unbiased	1.9999	2	0.0001
6	30	Biased	2.0001	1.9999	-0.0002
7	50	Biased	1.9998	2.0001	0.0003
8	30	Unbiased	1.9998	2.0001	0.0003
9	20	Unbiased	2	1.9998	-0.0002
10	50	Biased	2.0005	1.9998	-0.0007
11	30	Biased	1.9998	2	0.0002
12	0	Correlation	1.9998	2	0.0002
13	0	Correlation	2.0001	2	-0.0001
14	50	Unbiased	2.0002	1.9999	-0.0003
15	20	Biased	2.0001	2	-0.0001
16	20	Unbiased	2	2	0
17	20	Biased	2	2.0001	0.0001
18	20	Unbiased	2.0005	2.0001	-0.0004
19	20	Biased	1.9994	2	0.0006
20	50	Unbiased	2.0003	2	-0.0003
21	0	Correlation	2	2	0
22	50	Unbiased	2.0006	1.9999	-0.0007
23	0	Correlation	1.9999	2	0.0001
24	20	Biased	2.0001	2	-0.0001
26	50	Biased	2	2.0001	0.0001
27	30	Unbiased	2.0004	2	-0.0004
28	30	Biased	2	2	0
29	30	Unbiased	2.0001	2.0001	0
30	20	Biased	2.0001	2	-0.0001
31	30	Unbiased	1.9999	1.9999	0
33	30	Biased	2	2	0
34	50	Unbiased	2.0005	2	-0.0005
35	20	Unbiased	2	2	0
41	30	Biased	1.9999	1.9998	-0.0001

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.9998	2	2.0001	0.0001291	2	2	2	0	-0.0001	5e-05	0.0002	0.0001291
20	1.9994	2	2.0005	0.00026583	1.9998	2	2.0001	8.165e-05	-0.0004	-2e-05	0.0006	0.00025734
30	1.9998	2	2.0004	0.0001792	1.9998	2	2.0001	9.1894e-05	-0.0004	-3e-05	0.0003	0.00019465
50	1.9997	2.0002	2.0006	0.0003171	1.9998	2	2.0001	9.9443e-05	-0.0007	-0.00016	0.0004	0.00039777

Device Test: 28.10 VOLTAGE|OC/CS/5/5/0/0/5/100kHz//@V_CS_ILIM_OC





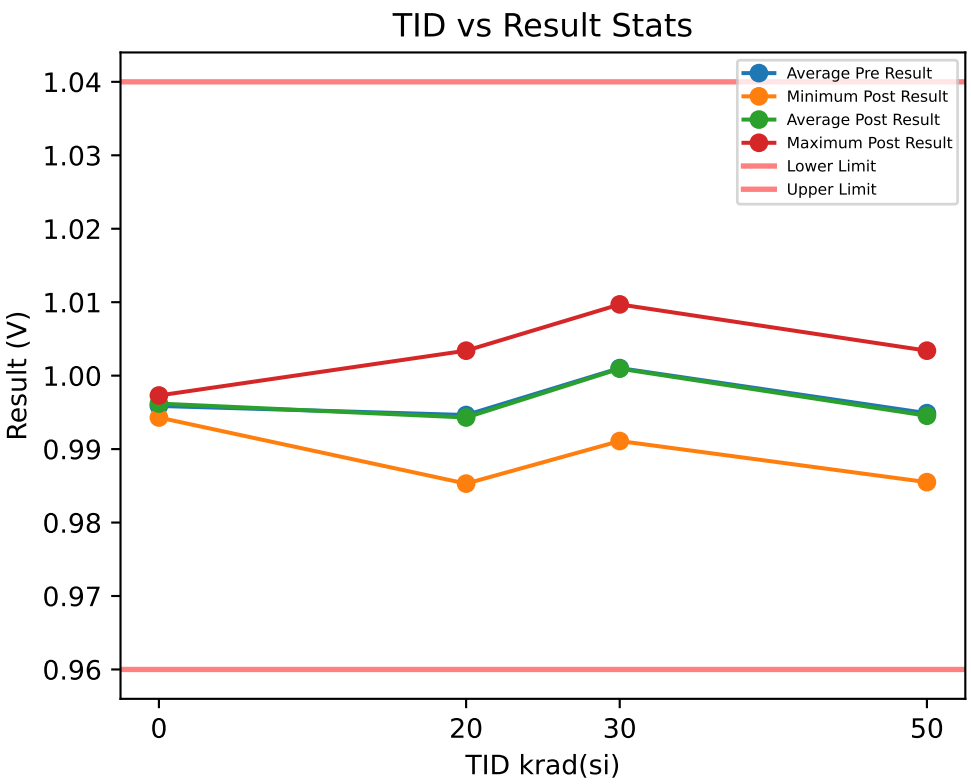
Test Results (Lower Limit = 0.96, Upper Limit = 1.04 (V))

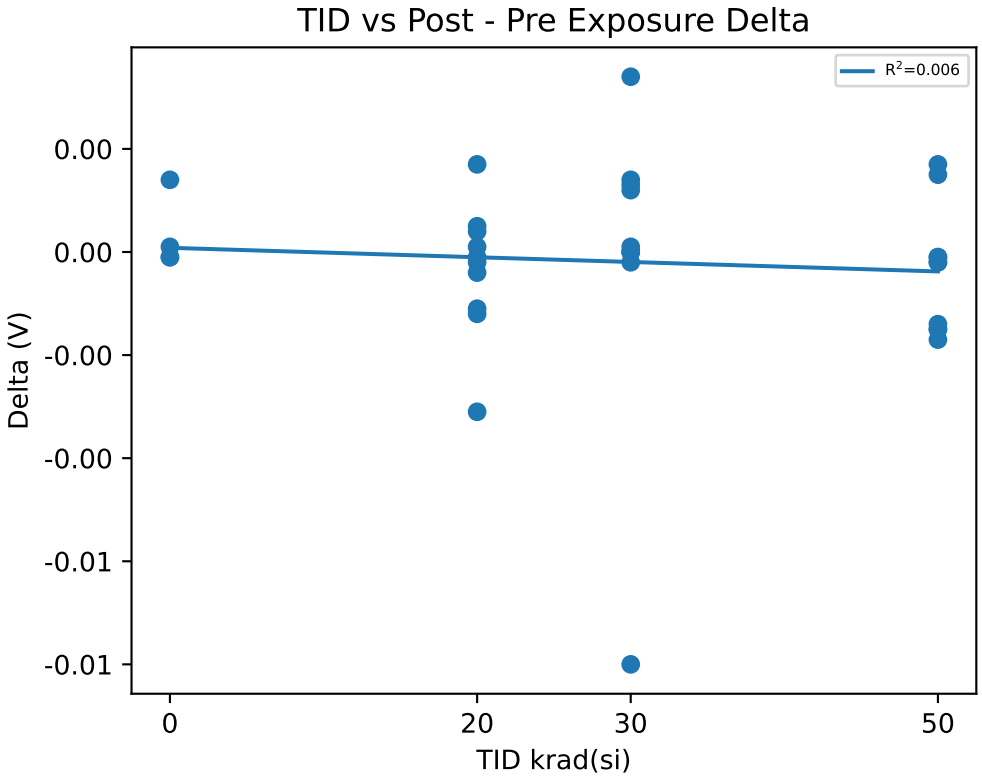
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	0.9912	0.9928	0.0016
2	20	Unbiased	0.987	0.9854	-0.0016
3	50	Biased	0.993	0.9944	0.0014
4	30	Unbiased	0.9915	0.9915	0
5	50	Unbiased	0.9945	0.993	-0.0015
6	30	Biased	1.0063	1.0078	0.0015
7	50	Biased	0.993	0.9928	-0.0002
8	30	Unbiased	0.9946	0.9972	0.0026
9	20	Unbiased	0.9871	0.9883	0.0012
10	50	Biased	0.9854	0.9853	-0.0001
11	30	Biased	0.9986	1.0003	0.0017
12	0	Correlation	0.9974	0.9973	-0.0001
13	0	Correlation	0.9974	0.9959	-0.0015
14	50	Unbiased	0.9944	0.993	-0.0014
15	20	Biased	1.0001	1.0019	0.0018
16	20	Unbiased	0.999	0.9992	0.0002
17	20	Biased	0.9897	0.9913	0.0016
18	20	Unbiased	0.996	0.9961	0.0001
19	20	Biased	0.9911	0.9899	-0.0012
20	50	Unbiased	1.0035	1.0033	-0.0002
21	0	Correlation	0.993	0.9926	-0.0004
22	50	Unbiased	0.9974	0.9959	-0.0015
23	0	Correlation	0.996	0.9961	0.0001
24	20	Biased	0.9945	0.9947	0.0002
26	50	Biased	1.0035	1.0024	-0.0011
27	30	Unbiased	1.0035	1.0051	0.0016
28	30	Biased	1.0079	1.0079	0
29	30	Unbiased	1.0051	1.0049	-0.0002
30	20	Biased	1.005	1.0048	-0.0002
31	30	Unbiased	1.0031	1.0033	0.0002
33	30	Biased	0.9974	0.9988	0.0014
34	50	Unbiased	0.9915	0.9913	-0.0002
35	20	Unbiased	0.9933	0.9932	-0.0001
41	30	Biased	1.0004	0.9916	-0.0088

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.993	0.99595	0.9974	0.0020744	0.9926	0.99547	0.9973	0.0020139	-0.0015	-0.000475	0.0001	0.00071356
20	0.987	0.99428	1.005	0.0058753	0.9854	0.99448	1.0048	0.0061452	-0.0016	0.0002	0.0018	0.0011045
30	0.9915	1.0008	1.0079	0.0053041	0.9915	1.0008	1.0079	0.0060487	-0.0088	-1.1102e-17	0.0026	0.0032308
50	0.9854	0.99474	1.0035	0.0055482	0.9853	0.99442	1.0033	0.0052379	-0.0015	-0.00032	0.0016	0.0011203

Device Test: 28.11 VOLTAGE|OC/CS/12/12/0/0/5/100kHz//@V_CS_ILIM_OC





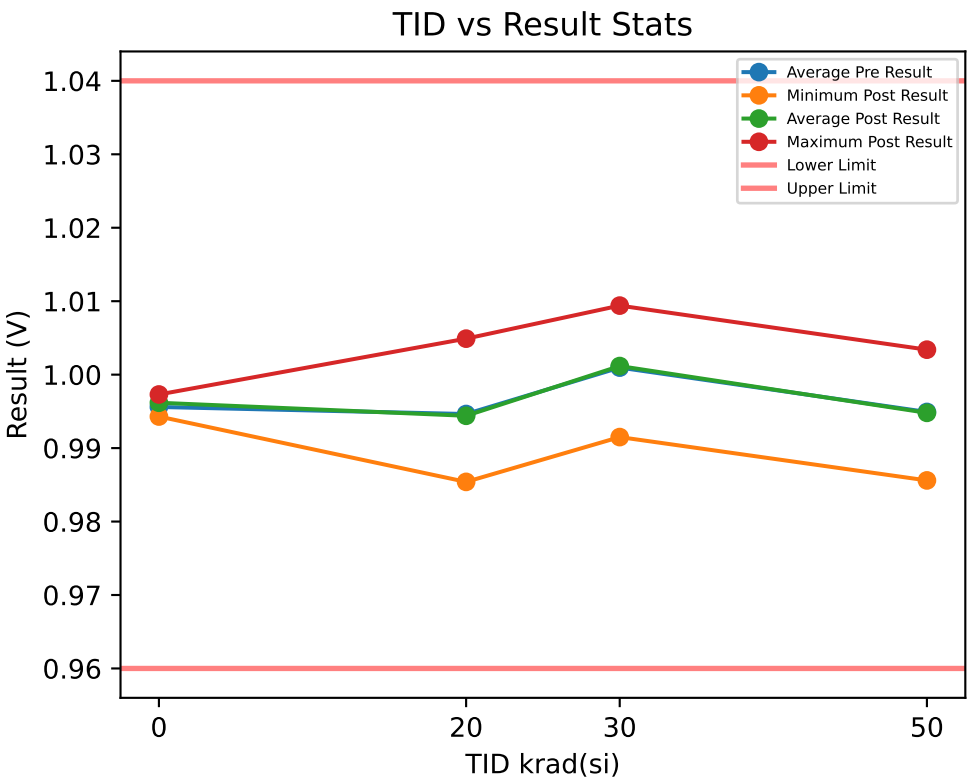
Test Results (Lower Limit = 0.96, Upper Limit = 1.04 (V))

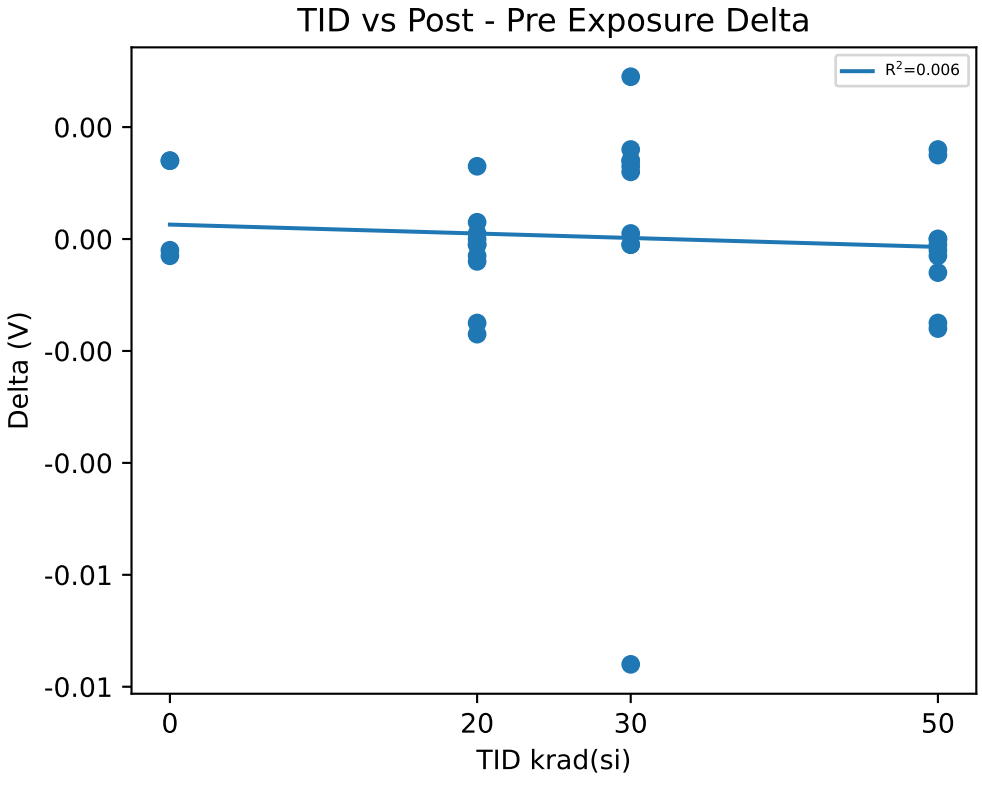
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	0.9912	0.9929	0.0017
2	20	Unbiased	0.9855	0.9853	-0.0002
3	50	Biased	0.9928	0.9943	0.0015
4	30	Unbiased	0.9915	0.9913	-0.0002
5	50	Unbiased	0.9945	0.993	-0.0015
6	30	Biased	1.0063	1.0097	0.0034
7	50	Biased	0.9929	0.9927	-0.0002
8	30	Unbiased	0.9945	0.9957	0.0012
9	20	Unbiased	0.9884	0.9883	-0.0001
10	50	Biased	0.9856	0.9855	-0.0001
11	30	Biased	0.999	1.0003	0.0013
12	0	Correlation	0.9974	0.9973	-0.0001
13	0	Correlation	0.9959	0.9973	0.0014
14	50	Unbiased	0.996	0.9946	-0.0014
15	20	Biased	1.0016	1.0021	0.0005
16	20	Unbiased	0.999	0.9991	0.0001
17	20	Biased	0.9897	0.9914	0.0017
18	20	Unbiased	0.996	0.9964	0.0004
19	20	Biased	0.991	0.9898	-0.0012
20	50	Unbiased	1.0035	1.0034	-0.0001
21	0	Correlation	0.9944	0.9943	-0.0001
22	50	Unbiased	0.9974	0.9959	-0.0015
23	0	Correlation	0.9958	0.9959	0.0001
24	20	Biased	0.9946	0.9942	-0.0004
26	50	Biased	1.0035	1.0018	-0.0017
27	30	Unbiased	1.0051	1.0051	0
28	30	Biased	1.008	1.0094	0.0014
29	30	Unbiased	1.0049	1.0049	0
30	20	Biased	1.0065	1.0034	-0.0031
31	30	Unbiased	1.0032	1.0033	0.0001
33	30	Biased	0.9987	0.9987	0
34	50	Unbiased	0.9915	0.9913	-0.0002
35	20	Unbiased	0.9941	0.993	-0.0011
41	30	Biased	0.9991	0.9911	-0.008

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.9944	0.99587	0.9974	0.0012258	0.9943	0.9962	0.9973	0.0014283	-0.0001	0.000325	0.0014	0.00072284
20	0.9855	0.99464	1.0065	0.0064151	0.9853	0.9943	1.0034	0.0059485	-0.0031	-0.00034	0.0017	0.0012747
30	0.9915	1.001	1.008	0.005368	0.9911	1.001	1.0097	0.0067454	-0.008	-8e-05	0.0034	0.0029933
50	0.9856	0.99489	1.0035	0.0055346	0.9855	0.99454	1.0034	0.0050967	-0.0017	-0.00035	0.0017	0.0012186

Device Test: 28.12 VOLTAGE|OC/CS/14/14/0/0/5/100kHz//@V_CS_ILIM_OC





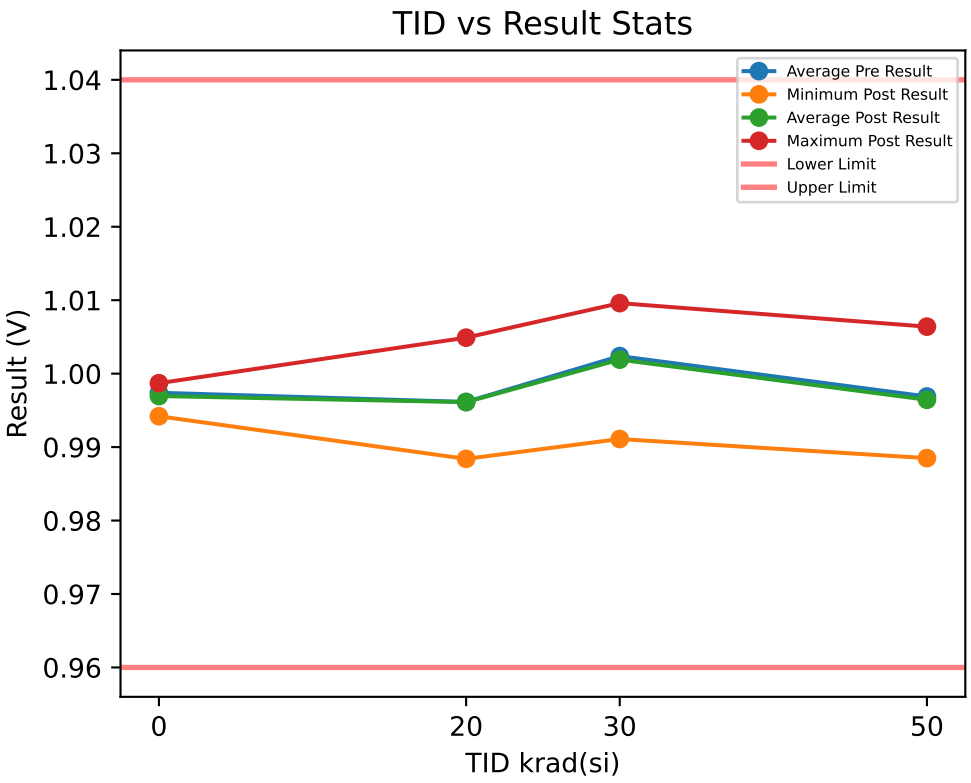
Test Results (Lower Limit = 0.96, Upper Limit = 1.04 (V))

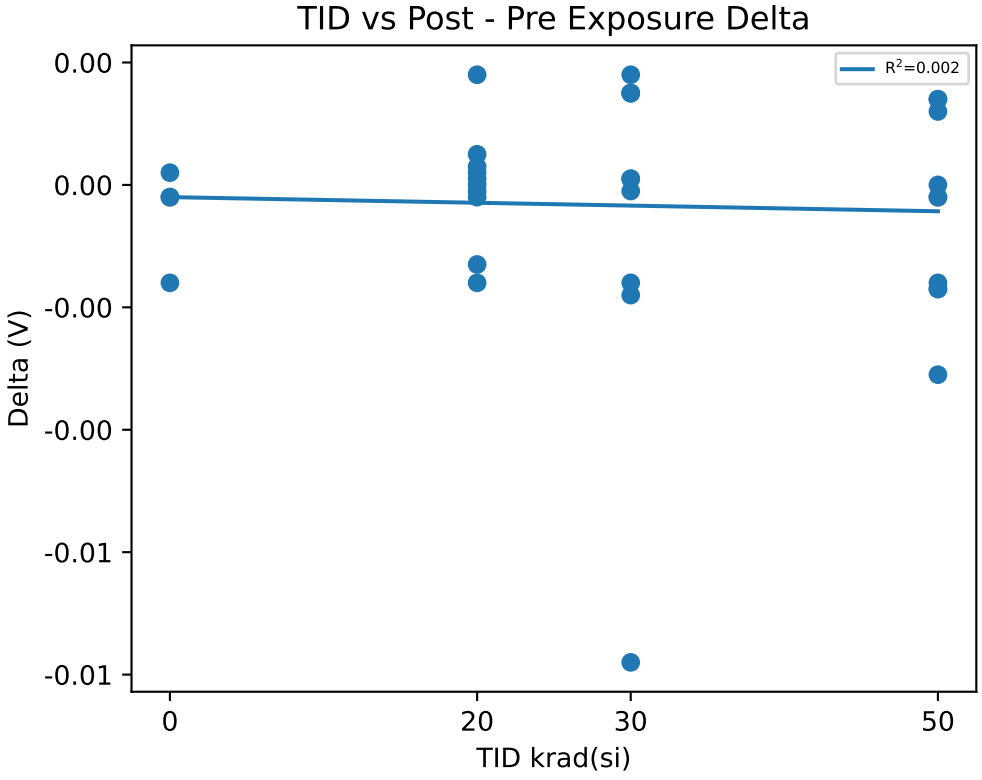
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	0.9912	0.9928	0.0016
2	20	Unbiased	0.9869	0.9854	-0.0015
3	50	Biased	0.9928	0.9943	0.0015
4	30	Unbiased	0.9914	0.9915	0.0001
5	50	Unbiased	0.9945	0.993	-0.0015
6	30	Biased	1.008	1.0094	0.0014
7	50	Biased	0.9933	0.9927	-0.0006
8	30	Unbiased	0.9945	0.9958	0.0013
9	20	Unbiased	0.9884	0.9883	-0.0001
10	50	Biased	0.9856	0.9856	0
11	30	Biased	0.9991	1.0003	0.0012
12	0	Correlation	0.9975	0.9972	-0.0003
13	0	Correlation	0.9959	0.9973	0.0014
14	50	Unbiased	0.9944	0.9941	-0.0003
15	20	Biased	1.0022	1.0018	-0.0004
16	20	Unbiased	0.999	0.9991	0.0001
17	20	Biased	0.99	0.9913	0.0013
18	20	Unbiased	0.996	0.9957	-0.0003
19	20	Biased	0.9915	0.9898	-0.0017
20	50	Unbiased	1.0035	1.0034	-0.0001
21	0	Correlation	0.9929	0.9943	0.0014
22	50	Unbiased	0.9975	0.9975	0
23	0	Correlation	0.9961	0.9959	-0.0002
24	20	Biased	0.9946	0.9946	0
26	50	Biased	1.0035	1.0033	-0.0002
27	30	Unbiased	1.0035	1.0051	0.0016
28	30	Biased	1.008	1.0094	0.0014
29	30	Unbiased	1.005	1.0049	-0.0001
30	20	Biased	1.005	1.0049	-0.0001
31	30	Unbiased	1.0035	1.0034	-0.0001
33	30	Biased	0.9974	1.0003	0.0029
34	50	Unbiased	0.9929	0.9913	-0.0016
35	20	Unbiased	0.9928	0.9931	0.0003
41	30	Biased	0.9992	0.9916	-0.0076

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.9929	0.9956	0.9975	0.0019356	0.9943	0.99618	0.9973	0.0014033	-0.0003	0.000575	0.0014	0.0009535
20	0.9869	0.99464	1.005	0.0059532	0.9854	0.9944	1.0049	0.0061418	-0.0017	-0.00024	0.0013	0.0008579
30	0.9914	1.001	1.008	0.0055847	0.9915	1.0012	1.0094	0.0065425	-0.0076	0.00021	0.0029	0.0028938
50	0.9856	0.99492	1.0035	0.0054389	0.9856	0.9948	1.0034	0.0054035	-0.0016	-0.00012	0.0016	0.0010528

Device Test: 28.13 VOLTAGE|OC/CS/4.5/4.5/0/0/4.5/500kHz//@V_CS_ILIM_OC





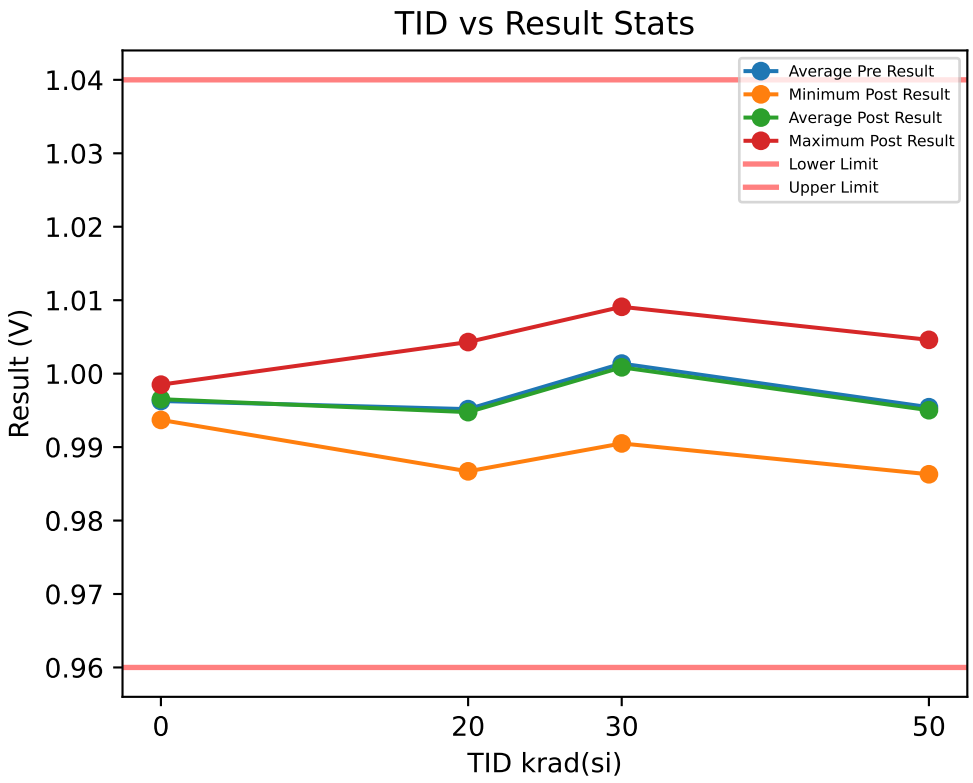
Test Results (Lower Limit = 0.96, Upper Limit = 1.04 (V))

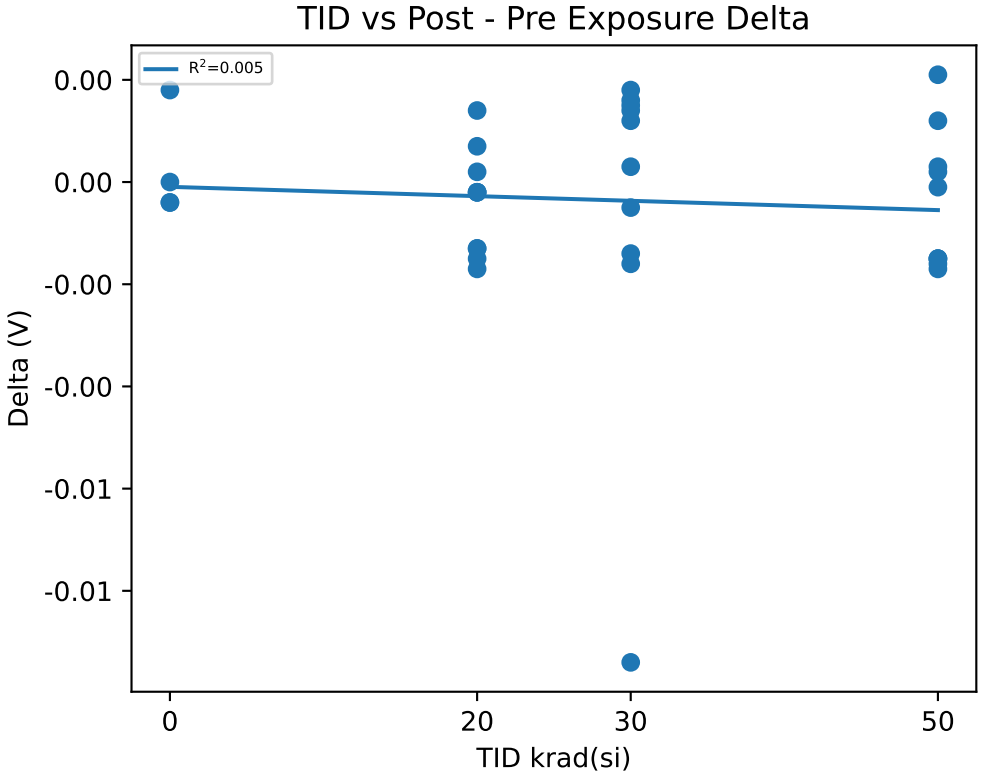
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	0.9946	0.9958	0.0012
2	20	Unbiased	0.9884	0.9884	0
3	50	Biased	0.9959	0.9973	0.0014
4	30	Unbiased	0.9929	0.9911	-0.0018
5	50	Unbiased	0.9944	0.9942	-0.0002
6	30	Biased	1.0081	1.0096	0.0015
7	50	Biased	0.9961	0.9944	-0.0017
8	30	Unbiased	0.9975	0.9993	0.0018
9	20	Unbiased	0.99	0.9899	-0.0001
10	50	Biased	0.9885	0.9885	0
11	30	Biased	1.0001	1.0002	0.0001
12	0	Correlation	0.9989	0.9987	-0.0002
13	0	Correlation	0.9989	0.9973	-0.0016
14	50	Unbiased	0.9975	0.9958	-0.0017
15	20	Biased	1.0016	1.0021	0.0005
16	20	Unbiased	1.0005	1.0003	-0.0002
17	20	Biased	0.9929	0.9947	0.0018
18	20	Unbiased	0.9975	0.9976	0.0001
19	20	Biased	0.9926	0.9913	-0.0013
20	50	Unbiased	1.005	1.0064	0.0014
21	0	Correlation	0.9944	0.9942	-0.0002
22	50	Unbiased	0.9989	0.9973	-0.0016
23	0	Correlation	0.9974	0.9976	0.0002
24	20	Biased	0.996	0.9962	0.0002
26	50	Biased	1.0035	1.0033	-0.0002
27	30	Unbiased	1.0066	1.0065	-0.0001
28	30	Biased	1.0079	1.0094	0.0015
29	30	Unbiased	1.0064	1.0048	-0.0016
30	20	Biased	1.0065	1.0049	-0.0016
31	30	Unbiased	1.0052	1.0053	0.0001
33	30	Biased	0.9989	1.0004	0.0015
34	50	Unbiased	0.9945	0.9914	-0.0031
35	20	Unbiased	0.9955	0.9958	0.0003
41	30	Biased	1.0003	0.9925	-0.0078

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.9944	0.9974	0.9989	0.0021213	0.9942	0.99695	0.9987	0.0019296	-0.0016	-0.00045	0.0002	0.00078951
20	0.9884	0.99615	1.0065	0.0055684	0.9884	0.99612	1.0049	0.005335	-0.0016	-3e-05	0.0018	0.00093814
30	0.9929	1.0024	1.0081	0.0051686	0.9911	1.0019	1.0096	0.0064426	-0.0078	-0.00048	0.0018	0.0028743
50	0.9885	0.99689	1.005	0.0047496	0.9885	0.99644	1.0064	0.0052301	-0.0031	-0.00045	0.0014	0.0015407

Device Test: 28.14 VOLTAGE|OC/CS/5/5/0/0/5/500kHz//@V_CS_ILIM_OC





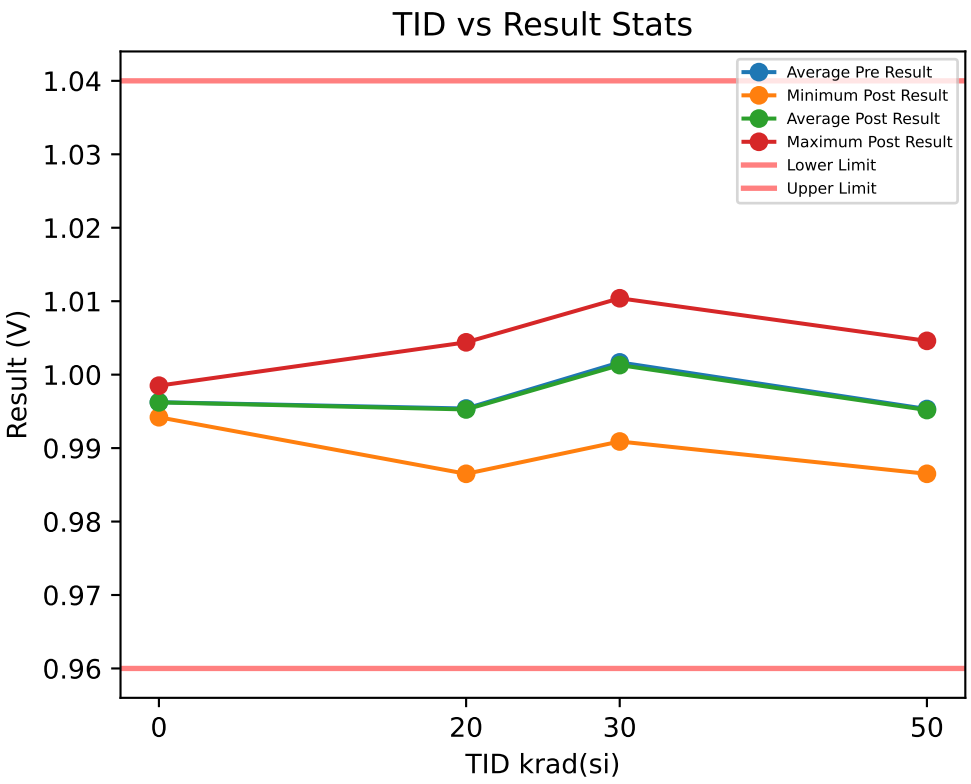
Test Results (Lower Limit = 0.96, Upper Limit = 1.04 (V))

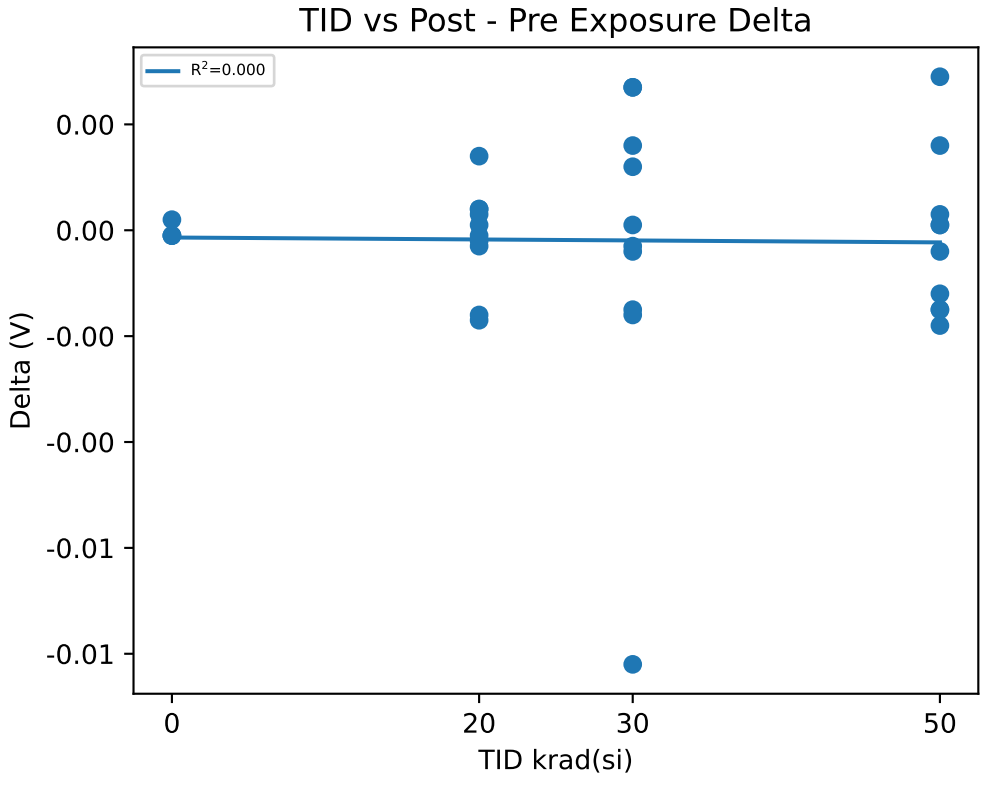
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	0.9926	0.9938	0.0012
2	20	Unbiased	0.9865	0.9867	0.0002
3	50	Biased	0.9936	0.9957	0.0021
4	30	Unbiased	0.9924	0.9908	-0.0016
5	50	Unbiased	0.9941	0.9925	-0.0016
6	30	Biased	1.0075	1.0091	0.0016
7	50	Biased	0.9938	0.9923	-0.0015
8	30	Unbiased	0.9955	0.9967	0.0012
9	20	Unbiased	0.9895	0.9878	-0.0017
10	50	Biased	0.9864	0.9863	-0.0001
11	30	Biased	0.9996	1.0014	0.0018
12	0	Correlation	0.9985	0.9985	0
13	0	Correlation	0.9972	0.9968	-0.0004
14	50	Unbiased	0.9956	0.9939	-0.0017
15	20	Biased	1.002	1.0027	0.0007
16	20	Unbiased	0.9999	0.9997	-0.0002
17	20	Biased	0.9909	0.9907	-0.0002
18	20	Unbiased	0.997	0.9957	-0.0013
19	20	Biased	0.9921	0.9908	-0.0013
20	50	Unbiased	1.0044	1.0046	0.0002
21	0	Correlation	0.9941	0.9937	-0.0004
22	50	Unbiased	0.9984	0.9969	-0.0015
23	0	Correlation	0.9953	0.9971	0.0018
24	20	Biased	0.994	0.9954	0.0014
26	50	Biased	1.003	1.0033	0.0003
27	30	Unbiased	1.0041	1.0044	0.0003
28	30	Biased	1.0074	1.0089	0.0015
29	30	Unbiased	1.0057	1.0043	-0.0014
30	20	Biased	1.0058	1.0043	-0.0015
31	30	Unbiased	1.0032	1.0027	-0.0005
33	30	Biased	0.9984	0.9998	0.0014
34	50	Unbiased	0.9924	0.9909	-0.0015
35	20	Unbiased	0.994	0.9938	-0.0002
41	30	Biased	0.9999	0.9905	-0.0094

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.9941	0.99628	0.9985	0.0019568	0.9937	0.99652	0.9985	0.0020238	-0.0004	0.00025	0.0018	0.0010504
20	0.9865	0.99517	1.0058	0.0059915	0.9867	0.99476	1.0043	0.0060207	-0.0017	-0.00041	0.0014	0.0010246
30	0.9924	1.0014	1.0075	0.0050829	0.9905	1.0009	1.0091	0.006562	-0.0094	-0.00051	0.0018	0.0033676
50	0.9864	0.99543	1.0044	0.0053033	0.9863	0.99502	1.0046	0.005516	-0.0017	-0.00041	0.0021	0.0013544

Device Test: 28.15 VOLTAGE|OC/CS/12/12/0/0/5/500kHz//@V_CS_ILIM_OC





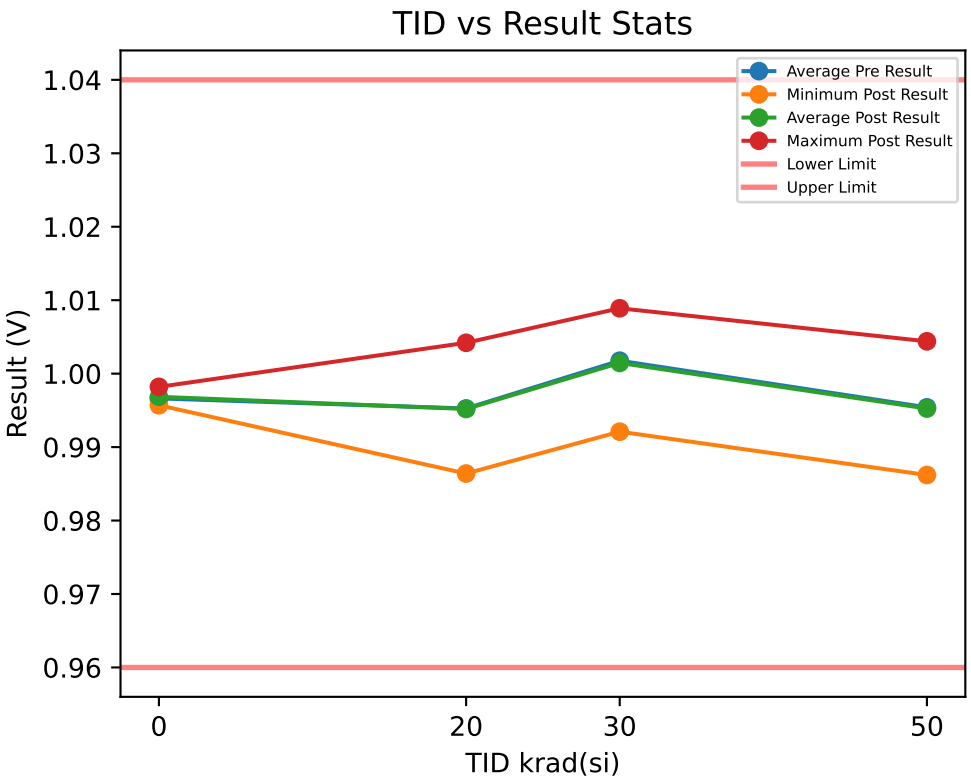
Test Results (Lower Limit = 0.96, Upper Limit = 1.04 (V))

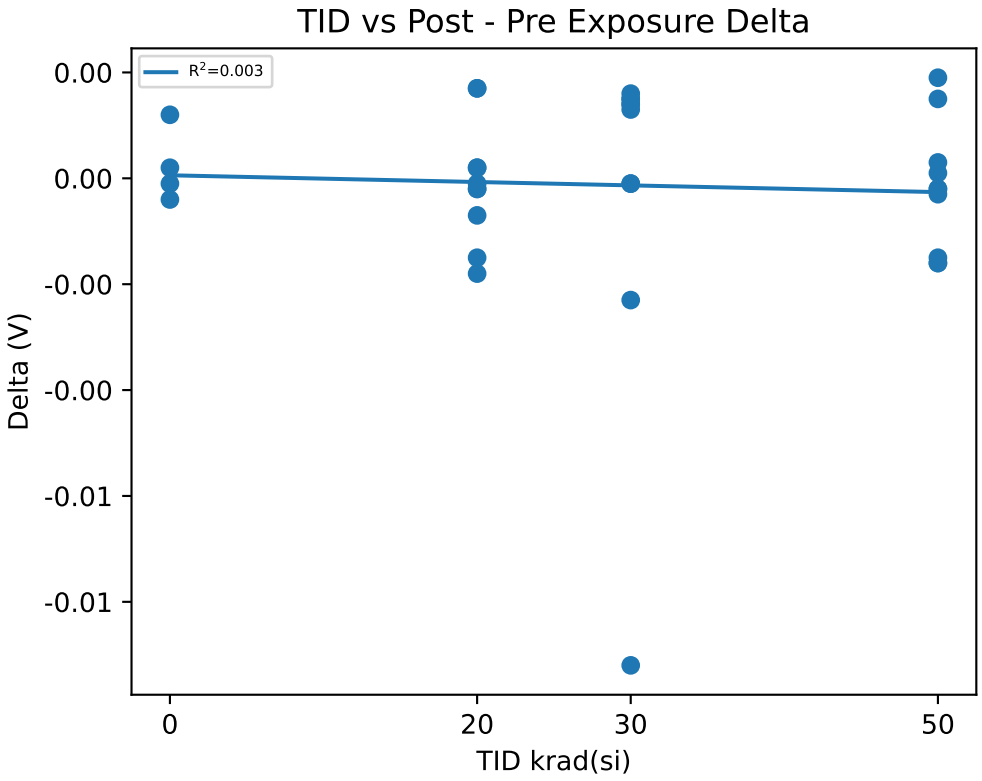
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	0.9924	0.994	0.0016
2	20	Unbiased	0.9864	0.9865	0.0001
3	50	Biased	0.9924	0.9953	0.0029
4	30	Unbiased	0.9924	0.9909	-0.0015
5	50	Unbiased	0.9939	0.9927	-0.0012
6	30	Biased	1.0077	1.0104	0.0027
7	50	Biased	0.9943	0.9939	-0.0004
8	30	Unbiased	0.994	0.9967	0.0027
9	20	Unbiased	0.9892	0.9896	0.0004
10	50	Biased	0.9862	0.9865	0.0003
11	30	Biased	1.0002	1.0014	0.0012
12	0	Correlation	0.9986	0.9985	-0.0001
13	0	Correlation	0.9969	0.9968	-0.0001
14	50	Unbiased	0.9956	0.9938	-0.0018
15	20	Biased	1.0027	1.0031	0.0004
16	20	Unbiased	0.9999	0.9998	-0.0001
17	20	Biased	0.9907	0.9921	0.0014
18	20	Unbiased	0.997	0.9968	-0.0002
19	20	Biased	0.9924	0.9908	-0.0016
20	50	Unbiased	1.0045	1.0046	0.0001
21	0	Correlation	0.994	0.9942	0.0002
22	50	Unbiased	0.9984	0.9969	-0.0015
23	0	Correlation	0.9955	0.9954	-0.0001
24	20	Biased	0.9954	0.9957	0.0003
26	50	Biased	1.0031	1.0032	0.0001
27	30	Unbiased	1.0044	1.0045	0.0001
28	30	Biased	1.0091	1.0088	-0.0003
29	30	Unbiased	1.006	1.0044	-0.0016
30	20	Biased	1.0061	1.0044	-0.0017
31	30	Unbiased	1.0046	1.0042	-0.0004
33	30	Biased	0.9982	0.9998	0.0016
34	50	Unbiased	0.9924	0.9909	-0.0015
35	20	Unbiased	0.9941	0.9938	-0.0003
41	30	Biased	1.0001	0.9919	-0.0082

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.994	0.99625	0.9986	0.0019638	0.9942	0.99623	0.9985	0.0018518	-0.0001	-2.5e-05	0.0002	0.00015
20	0.9864	0.99539	1.0061	0.0061717	0.9865	0.99526	1.0044	0.0058591	-0.0017	-0.00013	0.0014	0.00093101
30	0.9924	1.0017	1.0091	0.0056547	0.9909	1.0013	1.0104	0.0065596	-0.0082	-0.00037	0.0027	0.0031539
50	0.9862	0.99532	1.0045	0.0054383	0.9865	0.99518	1.0046	0.0053829	-0.0018	-0.00014	0.0029	0.001499

Device Test: 28.16 VOLTAGE|OC/CS/14/14/0/0/5/500kHz//@V_CS_ILIM_OC





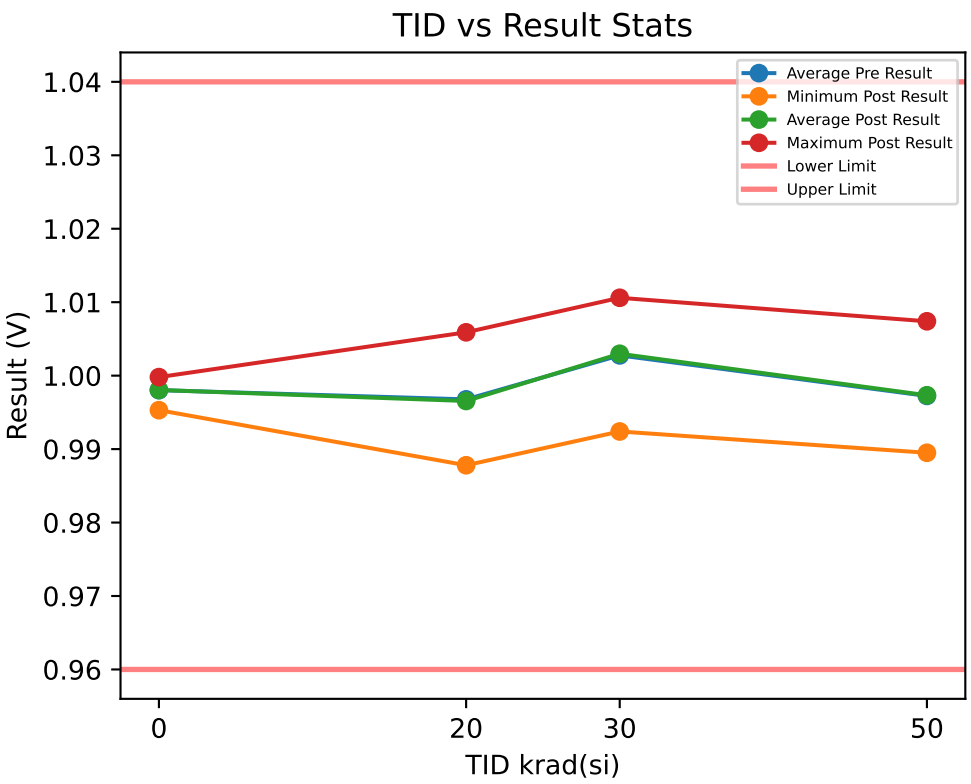
Test Results (Lower Limit = 0.96, Upper Limit = 1.04 (V))

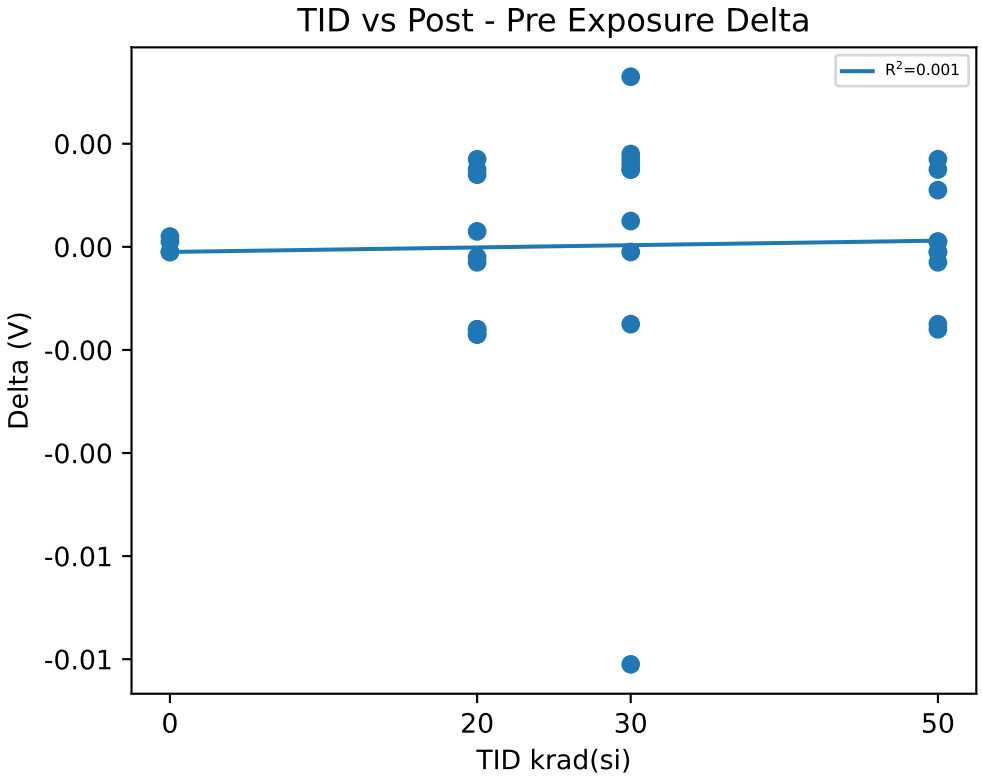
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	0.9924	0.9939	0.0015
2	20	Unbiased	0.9879	0.9864	-0.0015
3	50	Biased	0.9935	0.9954	0.0019
4	30	Unbiased	0.9924	0.9923	-0.0001
5	50	Unbiased	0.9941	0.9926	-0.0015
6	30	Biased	1.0075	1.0089	0.0014
7	50	Biased	0.9936	0.9939	0.0003
8	30	Unbiased	0.9955	0.9968	0.0013
9	20	Unbiased	0.9895	0.9893	-0.0002
10	50	Biased	0.9865	0.9862	-0.0003
11	30	Biased	0.9998	1.0014	0.0016
12	0	Correlation	0.9986	0.9982	-0.0004
13	0	Correlation	0.9969	0.9968	-0.0001
14	50	Unbiased	0.9955	0.9953	-0.0002
15	20	Biased	1.0011	1.0028	0.0017
16	20	Unbiased	1	0.9999	-0.0001
17	20	Biased	0.991	0.9927	0.0017
18	20	Unbiased	0.997	0.9972	0.0002
19	20	Biased	0.9911	0.9904	-0.0007
20	50	Unbiased	1.0046	1.0044	-0.0002
21	0	Correlation	0.9955	0.9957	0.0002
22	50	Unbiased	0.9985	0.9969	-0.0016
23	0	Correlation	0.9955	0.9967	0.0012
24	20	Biased	0.9954	0.9952	-0.0002
26	50	Biased	1.003	1.0031	0.0001
27	30	Unbiased	1.0046	1.006	0.0014
28	30	Biased	1.009	1.0089	-0.0001
29	30	Unbiased	1.0044	1.0059	0.0015
30	20	Biased	1.006	1.0042	-0.0018
31	30	Unbiased	1.0047	1.0024	-0.0023
33	30	Biased	0.9984	0.9999	0.0015
34	50	Unbiased	0.9924	0.9908	-0.0016
35	20	Unbiased	0.9936	0.9938	0.0002
41	30	Biased	1.0013	0.9921	-0.0092

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.9955	0.99663	0.9986	0.0014728	0.9957	0.99685	0.9982	0.0010279	-0.0004	0.000225	0.0012	0.00069462
20	0.9879	0.99526	1.006	0.0057785	0.9864	0.99519	1.0042	0.0058533	-0.0018	-7e-05	0.0017	0.001149
30	0.9924	1.0018	1.009	0.0052829	0.9921	1.0015	1.0089	0.0062145	-0.0092	-0.0003	0.0016	0.0033619
50	0.9865	0.99541	1.0046	0.0053517	0.9862	0.99525	1.0044	0.0053796	-0.0016	-0.00016	0.0019	0.0012131

Device Test: 28.17 VOLTAGE|OC/CS/4.5/4.5/0/0/4.5/1MHz//@V_CS_ILIM_OC





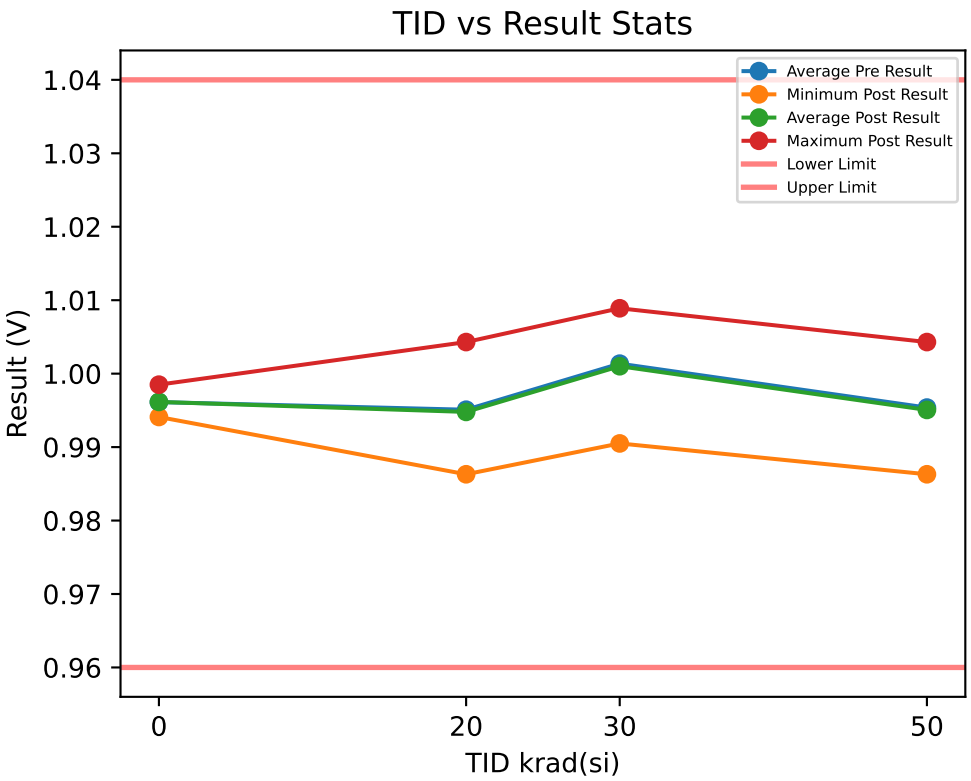
Test Results (Lower Limit = 0.96, Upper Limit = 1.04 (V))

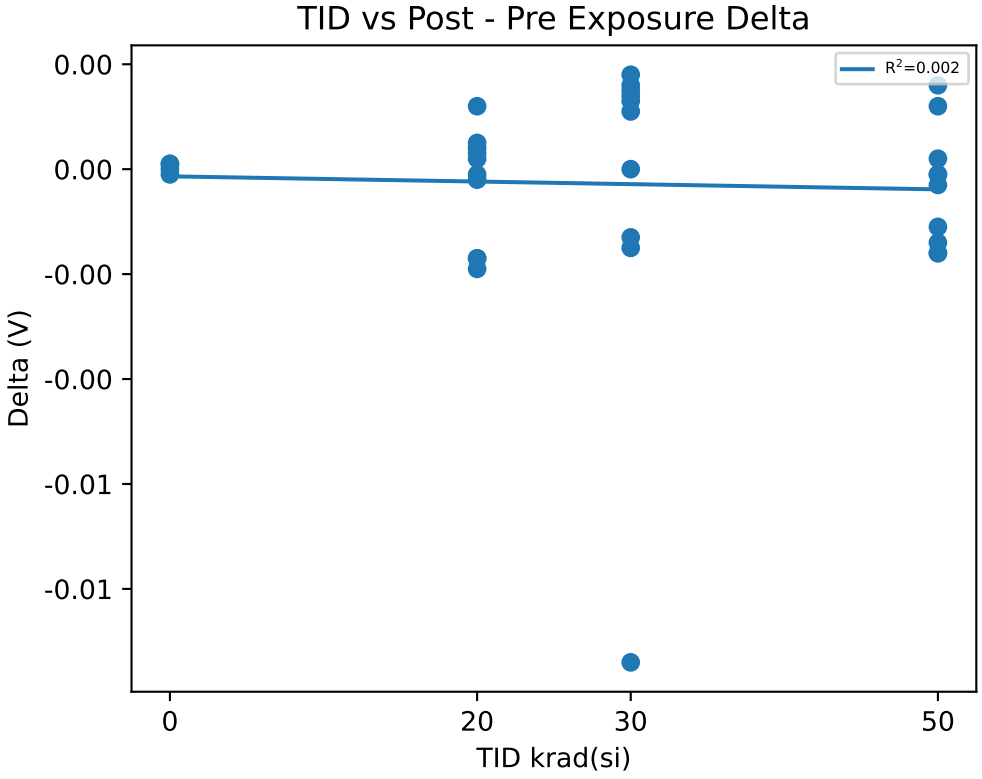
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	0.9952	0.9953	0.0001
2	20	Unbiased	0.9895	0.9878	-0.0017
3	50	Biased	0.9968	0.9983	0.0015
4	30	Unbiased	0.9939	0.9924	-0.0015
5	50	Unbiased	0.9956	0.9953	-0.0003
6	30	Biased	1.0073	1.0106	0.0033
7	50	Biased	0.9955	0.9954	-0.0001
8	30	Unbiased	0.9985	1.0002	0.0017
9	20	Unbiased	0.9907	0.991	0.0003
10	50	Biased	0.9894	0.9895	0.0001
11	30	Biased	0.9998	1.0016	0.0018
12	0	Correlation	0.9999	0.9998	-0.0001
13	0	Correlation	0.9982	0.9984	0.0002
14	50	Unbiased	0.997	0.9969	-0.0001
15	20	Biased	1.0016	1.0031	0.0015
16	20	Unbiased	1.0015	1.0012	-0.0003
17	20	Biased	0.9922	0.9936	0.0014
18	20	Unbiased	0.9985	0.9969	-0.0016
19	20	Biased	0.9938	0.9922	-0.0016
20	50	Unbiased	1.0057	1.0074	0.0017
21	0	Correlation	0.9952	0.9953	0.0001
22	50	Unbiased	1.0001	0.9986	-0.0015
23	0	Correlation	0.9988	0.9987	-0.0001
24	20	Biased	0.997	0.9968	-0.0002
26	50	Biased	1.0031	1.0042	0.0011
27	30	Unbiased	1.0059	1.0075	0.0016
28	30	Biased	1.009	1.0105	0.0015
29	30	Unbiased	1.006	1.0059	-0.0001
30	20	Biased	1.0076	1.0059	-0.0017
31	30	Unbiased	1.0056	1.0061	0.0005
33	30	Biased	0.9999	1.0014	0.0015
34	50	Unbiased	0.994	0.9924	-0.0016
35	20	Unbiased	0.9953	0.997	0.0017
41	30	Biased	1.0017	0.9936	-0.0081

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.9952	0.99802	0.9999	0.0020106	0.9953	0.99805	0.9998	0.0019296	-0.0001	2.5e-05	0.0002	0.00015
20	0.9895	0.99677	1.0076	0.0056529	0.9878	0.99655	1.0059	0.0056502	-0.0017	-0.00022	0.0017	0.0014038
30	0.9939	1.0028	1.009	0.0047456	0.9924	1.003	1.0106	0.0063714	-0.0081	0.00022	0.0033	0.0031923
50	0.9894	0.99724	1.0057	0.0046689	0.9895	0.99733	1.0074	0.0052591	-0.0016	9e-05	0.0017	0.001116

Device Test: 28.18 VOLTAGE|OC/CS/5/5/0/0/5/1MHz//@V_CS_ILIM_OC





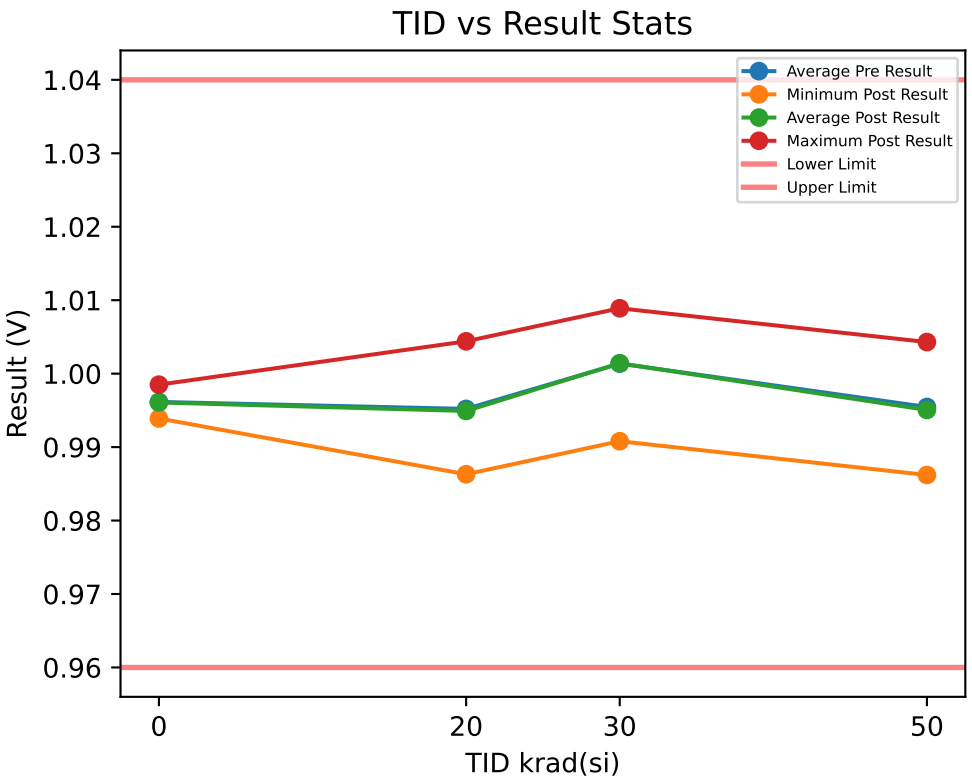
Test Results (Lower Limit = 0.96, Upper Limit = 1.04 (V))

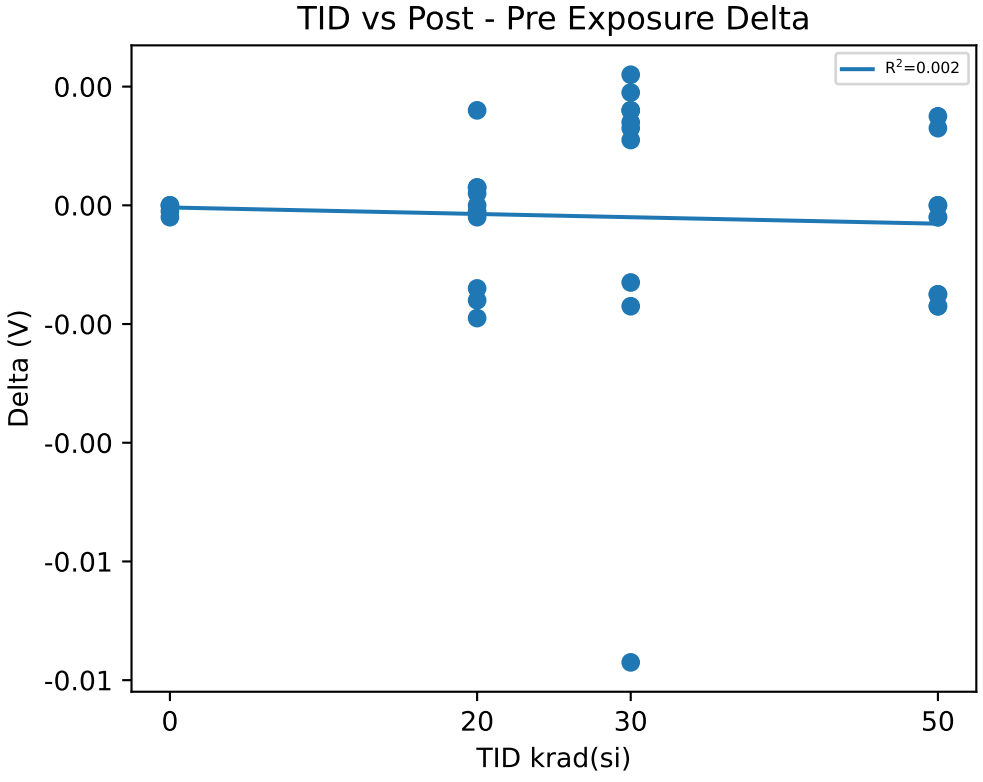
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	0.9922	0.9938	0.0016
2	20	Unbiased	0.9865	0.9863	-0.0002
3	50	Biased	0.9941	0.9953	0.0012
4	30	Unbiased	0.9925	0.991	-0.0015
5	50	Unbiased	0.9937	0.9926	-0.0011
6	30	Biased	1.0076	1.0089	0.0013
7	50	Biased	0.9936	0.9938	0.0002
8	30	Unbiased	0.9955	0.9966	0.0011
9	20	Unbiased	0.9896	0.9895	-0.0001
10	50	Biased	0.9864	0.9863	-0.0001
11	30	Biased	0.9999	1.0014	0.0015
12	0	Correlation	0.9985	0.9985	0
13	0	Correlation	0.9967	0.9968	0.0001
14	50	Unbiased	0.9955	0.9939	-0.0016
15	20	Biased	1.0011	1.0016	0.0005
16	20	Unbiased	0.9999	1.0002	0.0003
17	20	Biased	0.9907	0.9909	0.0002
18	20	Unbiased	0.9971	0.9952	-0.0019
19	20	Biased	0.9925	0.9908	-0.0017
20	50	Unbiased	1.0044	1.0043	-0.0001
21	0	Correlation	0.994	0.9941	0.0001
22	50	Unbiased	0.9984	0.997	-0.0014
23	0	Correlation	0.9953	0.9952	-0.0001
24	20	Biased	0.9939	0.9951	0.0012
26	50	Biased	1.003	1.0027	-0.0003
27	30	Unbiased	1.0041	1.0059	0.0018
28	30	Biased	1.0075	1.0089	0.0014
29	30	Unbiased	1.0057	1.0044	-0.0013
30	20	Biased	1.006	1.0043	-0.0017
31	30	Unbiased	1.0027	1.0027	0
33	30	Biased	0.9982	0.9998	0.0016
34	50	Unbiased	0.9925	0.9909	-0.0016
35	20	Unbiased	0.9936	0.994	0.0004
41	30	Biased	0.9999	0.9905	-0.0094

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.994	0.99613	0.9985	0.0019294	0.9941	0.99615	0.9985	0.0019192	-0.0001	2.5e-05	0.0001	9.5743e-05
20	0.9865	0.99509	1.006	0.0059242	0.9863	0.99479	1.0043	0.0057551	-0.0019	-0.0003	0.0012	0.0010812
30	0.9925	1.0014	1.0076	0.0050757	0.9905	1.001	1.0089	0.0066206	-0.0094	-0.00035	0.0018	0.0033991
50	0.9864	0.99538	1.0044	0.0053254	0.9863	0.99506	1.0043	0.0052934	-0.0016	-0.00032	0.0016	0.0011263

Device Test: 28.19 VOLTAGE|OC/CS/12/12/0/0/5/1MHz//@V_CS_ILIM_OC





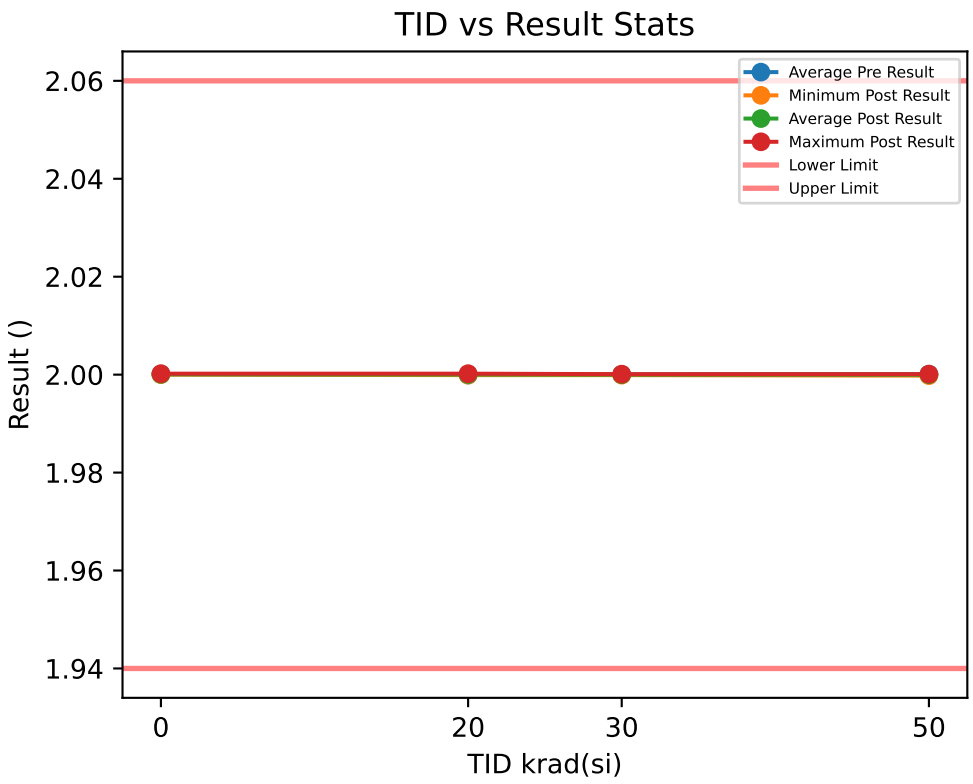
Test Results (Lower Limit = 0.96, Upper Limit = 1.04 (V))

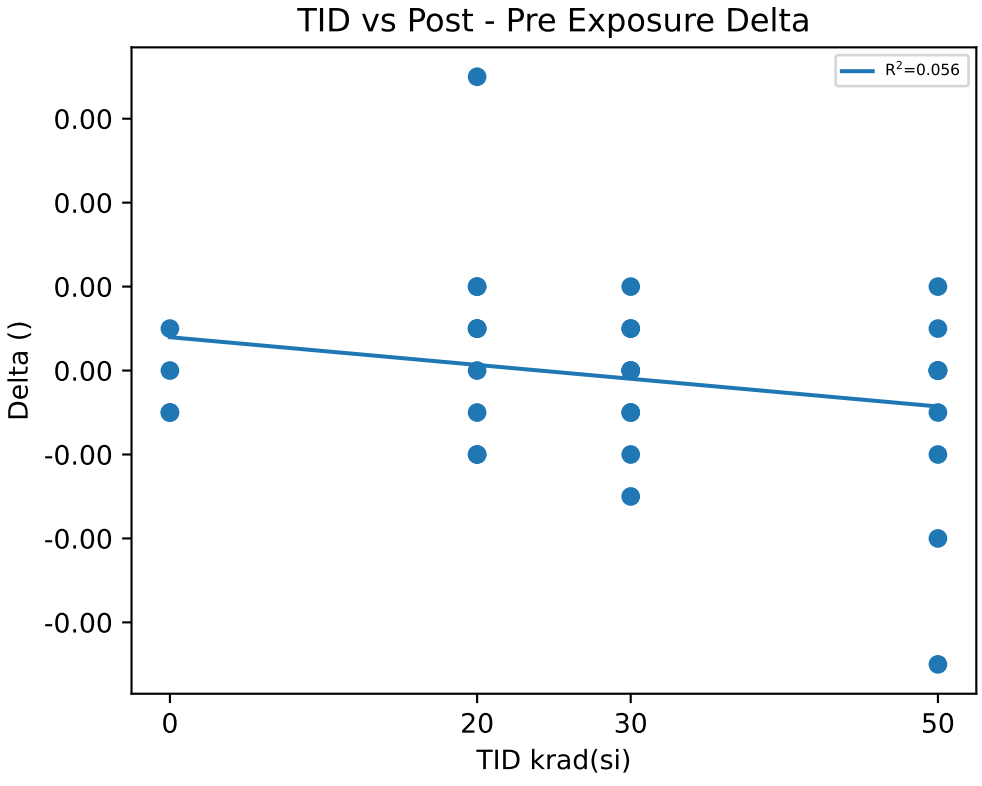
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	0.9924	0.9939	0.0015
2	20	Unbiased	0.9865	0.9863	-0.0002
3	50	Biased	0.9941	0.9954	0.0013
4	30	Unbiased	0.9925	0.9908	-0.0017
5	50	Unbiased	0.9942	0.9925	-0.0017
6	30	Biased	1.0075	1.0089	0.0014
7	50	Biased	0.9939	0.9939	0
8	30	Unbiased	0.9954	0.9973	0.0019
9	20	Unbiased	0.9894	0.9896	0.0002
10	50	Biased	0.9864	0.9862	-0.0002
11	30	Biased	0.9995	1.0011	0.0016
12	0	Correlation	0.9985	0.9985	0
13	0	Correlation	0.9969	0.9968	-0.0001
14	50	Unbiased	0.9954	0.9939	-0.0015
15	20	Biased	1.0011	1.0014	0.0003
16	20	Unbiased	0.9999	1.0002	0.0003
17	20	Biased	0.9907	0.9923	0.0016
18	20	Unbiased	0.997	0.9951	-0.0019
19	20	Biased	0.9923	0.9907	-0.0016
20	50	Unbiased	1.0045	1.0043	-0.0002
21	0	Correlation	0.9939	0.9939	0
22	50	Unbiased	0.9985	0.9968	-0.0017
23	0	Correlation	0.9953	0.9951	-0.0002
24	20	Biased	0.9955	0.9954	-0.0001
26	50	Biased	1.0028	1.0028	0
27	30	Unbiased	1.0047	1.0058	0.0011
28	30	Biased	1.0075	1.0088	0.0013
29	30	Unbiased	1.0057	1.0044	-0.0013
30	20	Biased	1.0058	1.0044	-0.0014
31	30	Unbiased	1.0026	1.0048	0.0022
33	30	Biased	0.9982	0.9998	0.0016
34	50	Unbiased	0.9924	0.9909	-0.0015
35	20	Unbiased	0.9938	0.9938	0
41	30	Biased	1.0001	0.9924	-0.0077

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.9939	0.99615	0.9985	0.0019891	0.9939	0.99608	0.9985	0.0020073	-0.0002	-7.5e-05	0	9.5743e-05
20	0.9865	0.9952	1.0058	0.0058929	0.9863	0.99492	1.0044	0.0056621	-0.0019	-0.00028	0.0016	0.0010633
30	0.9925	1.0014	1.0075	0.0051206	0.9908	1.0014	1.0089	0.0063574	-0.0077	4e-05	0.0022	0.0030237
50	0.9864	0.99546	1.0045	0.0052865	0.9862	0.99506	1.0043	0.0053211	-0.0017	-0.0004	0.0015	0.0011879

Device Test: 28.2 LEVEL|RATIO/CS/5/5/0/0/5/500kHz//@C_CS_R





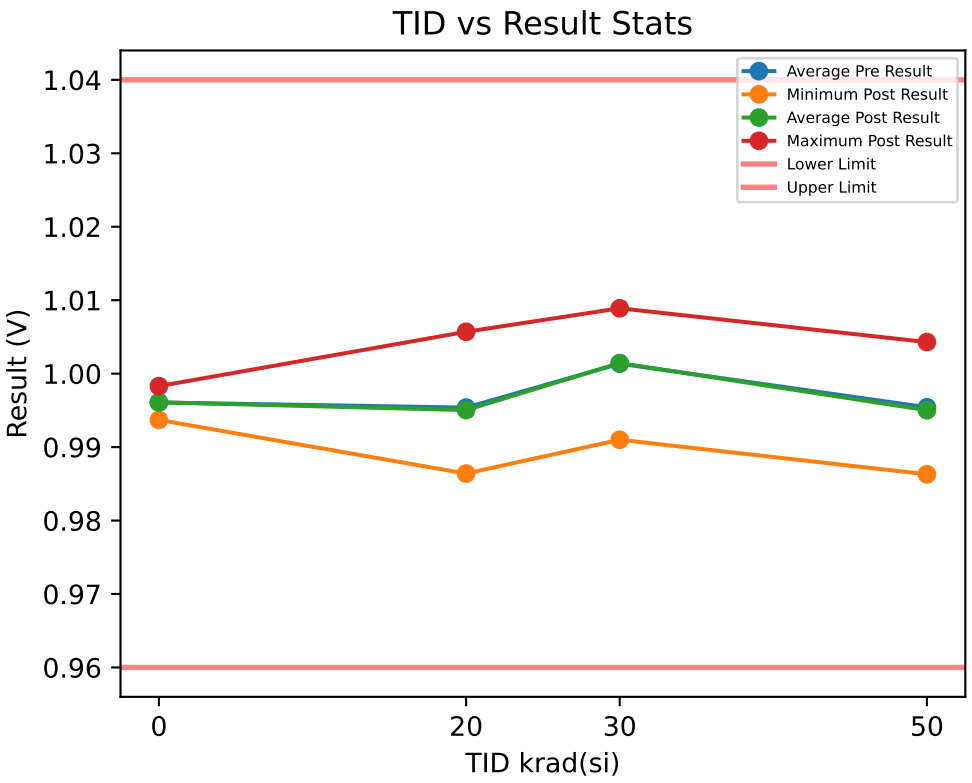
Test Results (Lower Limit = 1.94, Upper Limit = 2.06 ())

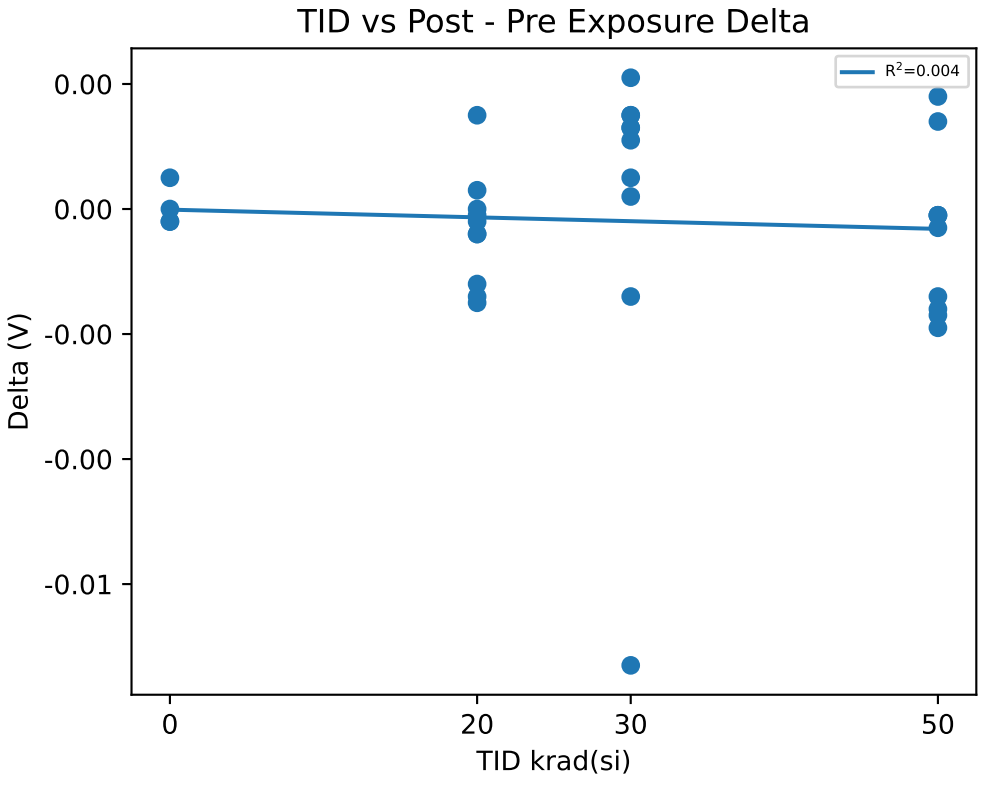
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	2.0001	2	-0.0001
2	20	Unbiased	2.0001	1.9999	-0.0002
3	50	Biased	2	2	0
4	30	Unbiased	1.9998	1.9999	0.0001
5	50	Unbiased	2.0001	2.0001	0
6	30	Biased	2.0001	2.0001	0
7	50	Biased	2.0001	2.0001	0
8	30	Unbiased	1.9999	2	0.0001
9	20	Unbiased	2	2	0
10	50	Biased	1.9999	2.0001	0.0002
11	30	Biased	2	2	0
12	0	Correlation	2.0001	2	-0.0001
13	0	Correlation	2.0001	2	-0.0001
14	50	Unbiased	2.0002	1.9998	-0.0004
15	20	Biased	2.0001	2	-0.0001
16	20	Unbiased	2.0001	1.9999	-0.0002
17	20	Biased	2.0001	2.0002	0.0001
18	20	Unbiased	1.9998	2	0.0002
19	20	Biased	1.9994	2.0001	0.0007
20	50	Unbiased	2	1.9998	-0.0002
21	0	Correlation	2.0001	2.0002	0.0001
22	50	Unbiased	1.9998	1.9999	0.0001
23	0	Correlation	2.0001	2.0001	0
24	20	Biased	1.9998	2	0.0002
26	50	Biased	2.0001	2.0001	0
27	30	Unbiased	2.0001	1.9999	-0.0002
28	30	Biased	2.0002	1.9999	-0.0003
29	30	Unbiased	2.0001	2	-0.0001
30	20	Biased	1.9999	2	0.0001
31	30	Unbiased	1.9999	2.0001	0.0002
33	30	Biased	2.0001	2	-0.0001
34	50	Unbiased	2.0007	2	-0.0007
35	20	Unbiased	2	2.0001	0.0001
41	30	Biased	2.0001	2.0001	0

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.0001	2.0001	2.0001	0	2	2.0001	2.0002	9.5743e-05	-0.0001	-2.5e-05	0.0001	9.5743e-05
20	1.9994	1.9999	2.0001	0.00022136	1.9999	2	2.0002	9.1894e-05	-0.0002	9e-05	0.0007	0.00026013
30	1.9998	2	2.0002	0.00012517	1.9999	2	2.0001	8.165e-05	-0.0003	-3e-05	0.0002	0.00014944
50	1.9998	2.0001	2.0007	0.00024037	1.9998	2	2.0001	0.00011972	-0.0007	-0.00011	0.0002	0.00026437

Device Test: 28.20 VOLTAGE|OC/CS/14/14/0/0/5/1MHz//@V_CS_ILIM_OC





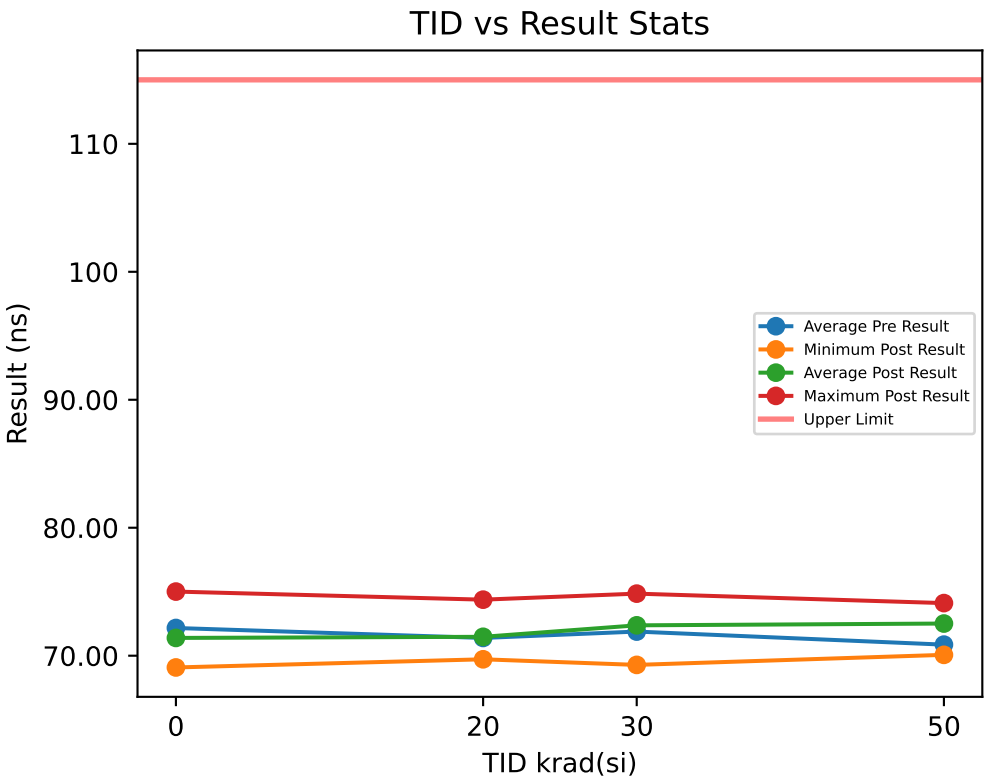
Test Results (Lower Limit = 0.96, Upper Limit = 1.04 (V))

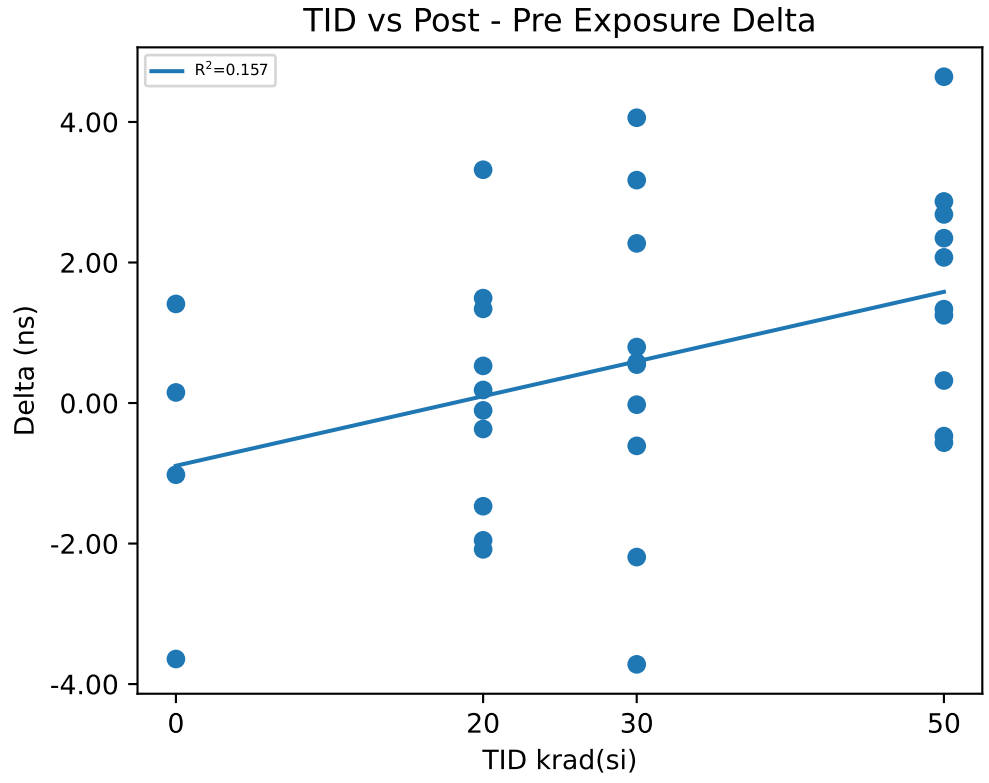
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	0.9925	0.9939	0.0014
2	20	Unbiased	0.9879	0.9864	-0.0015
3	50	Biased	0.9936	0.9954	0.0018
4	30	Unbiased	0.9924	0.991	-0.0014
5	50	Unbiased	0.9939	0.9925	-0.0014
6	30	Biased	1.0075	1.0088	0.0013
7	50	Biased	0.994	0.9937	-0.0003
8	30	Unbiased	0.9955	0.9966	0.0011
9	20	Unbiased	0.9895	0.9893	-0.0002
10	50	Biased	0.9864	0.9863	-0.0001
11	30	Biased	0.9995	1.0016	0.0021
12	0	Correlation	0.9985	0.9983	-0.0002
13	0	Correlation	0.997	0.9968	-0.0002
14	50	Unbiased	0.9955	0.9936	-0.0019
15	20	Biased	1.0017	1.0013	-0.0004
16	20	Unbiased	1.0001	1.0001	0
17	20	Biased	0.9907	0.9922	0.0015
18	20	Unbiased	0.997	0.9958	-0.0012
19	20	Biased	0.9921	0.9907	-0.0014
20	50	Unbiased	1.0044	1.0043	-0.0001
21	0	Correlation	0.9937	0.9937	0
22	50	Unbiased	0.9984	0.9968	-0.0016
23	0	Correlation	0.9951	0.9956	0.0005
24	20	Biased	0.9955	0.9951	-0.0004
26	50	Biased	1.003	1.0029	-0.0001
27	30	Unbiased	1.0047	1.006	0.0013
28	30	Biased	1.0074	1.0089	0.0015
29	30	Unbiased	1.0057	1.0059	0.0002
30	20	Biased	1.0058	1.0057	-0.0001
31	30	Unbiased	1.0029	1.0034	0.0005
33	30	Biased	0.9982	0.9997	0.0015
34	50	Unbiased	0.9925	0.9908	-0.0017
35	20	Unbiased	0.9935	0.9938	0.0003
41	30	Biased	0.9998	0.9925	-0.0073

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.9937	0.99608	0.9985	0.0021077	0.9937	0.9961	0.9983	0.0019442	-0.0002	2.5e-05	0.0005	0.0003304
20	0.9879	0.99538	1.0058	0.005775	0.9864	0.99504	1.0057	0.0059165	-0.0015	-0.00034	0.0015	0.00089468
30	0.9924	1.0014	1.0075	0.0051321	0.991	1.0014	1.0089	0.0064096	-0.0073	8e-05	0.0021	0.0027684
50	0.9864	0.99542	1.0044	0.0053024	0.9863	0.99502	1.0043	0.005341	-0.0019	-0.0004	0.0018	0.0012798

Device Test: 28.21 TIMING|DELAY/CS/4.5/4.5/0/0/4.5/100kHz//@CS_ILIM_DELAY





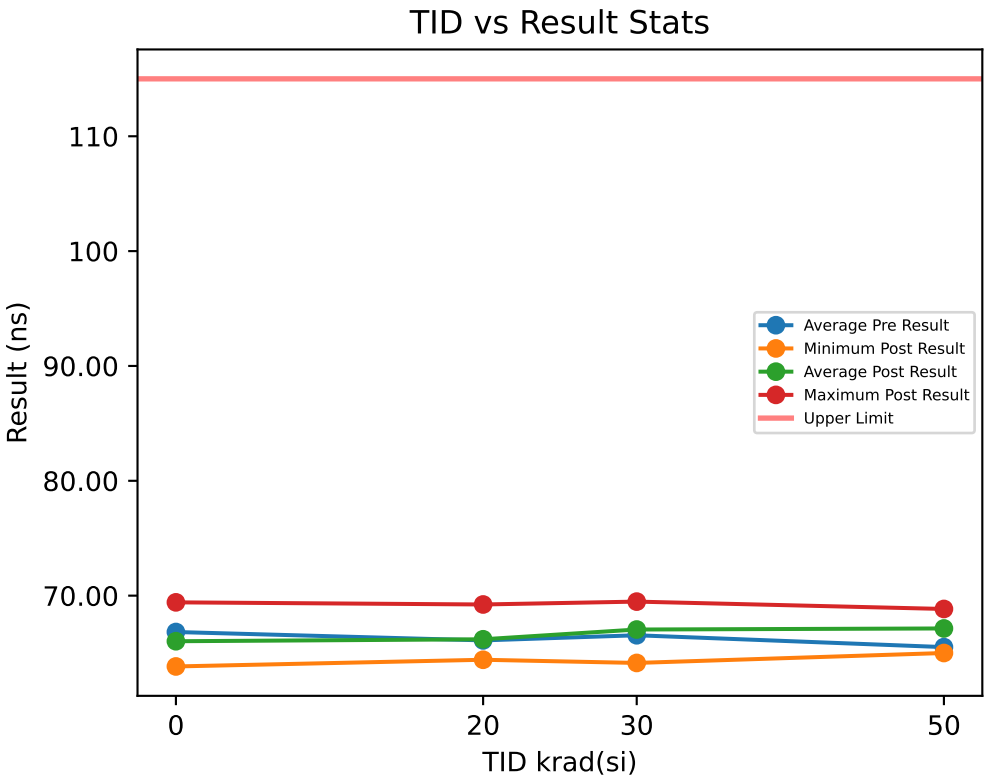
Test Results (Upper Limit = 115.0 (ns))

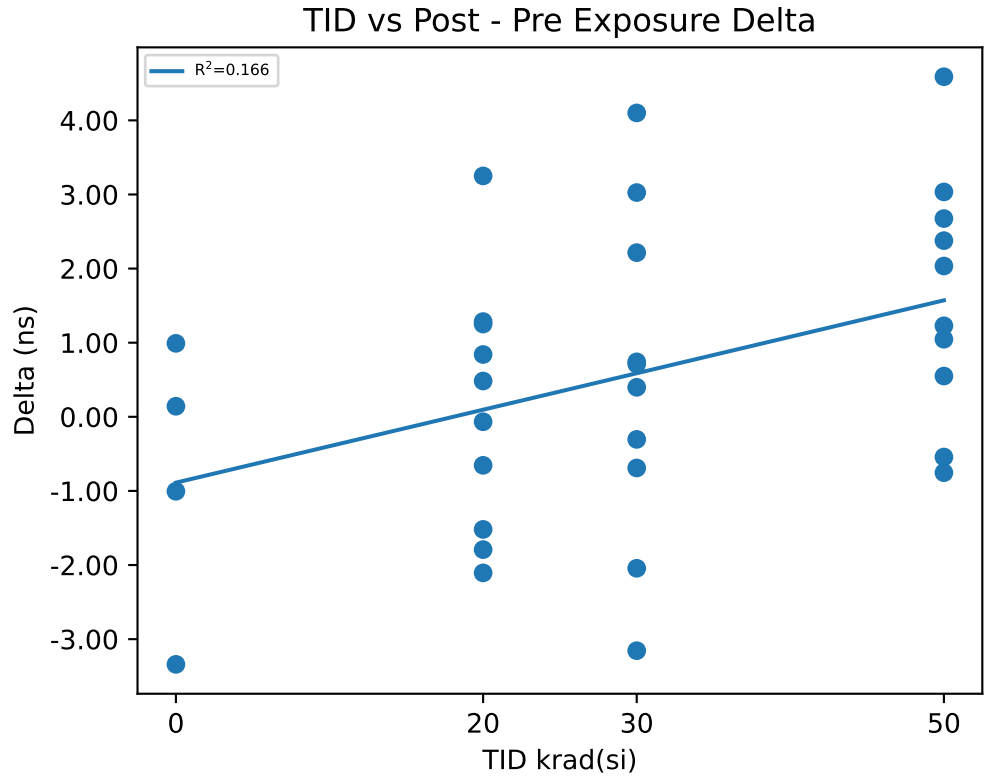
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	69.304	71.377	2.0727
2	20	Unbiased	68.689	70.028	1.3399
3	50	Biased	72.196	71.725	-0.4709
4	30	Unbiased	70.33	70.877	0.5466
5	50	Unbiased	70.864	73.733	2.8689
6	30	Biased	70.79	74.85	4.06
7	50	Biased	74.21	73.646	-0.5645
8	30	Unbiased	71.475	69.282	-2.1924
9	20	Unbiased	69.583	71.076	1.4933
10	50	Biased	69.061	73.705	4.6438
11	30	Biased	72.911	73.707	0.7966
12	0	Correlation	73.601	75.011	1.4104
13	0	Correlation	71.108	71.259	0.1506
14	50	Unbiased	69.295	71.979	2.6843
15	20	Biased	73.851	74.38	0.5287
16	20	Unbiased	71.802	69.72	-2.0824
17	20	Biased	70.984	70.615	-0.3693
18	20	Unbiased	70.551	70.446	-0.1048
19	20	Biased	72.002	70.533	-1.4688
20	50	Unbiased	73.791	74.111	0.3204
21	0	Correlation	70.102	69.082	-1.0204
22	50	Unbiased	70.084	72.43	2.3463
23	0	Correlation	73.85	70.207	-3.6429
24	20	Biased	72.977	71.023	-1.9541
26	50	Biased	71.025	72.362	1.3363
27	30	Unbiased	73.64	73.617	-0.0234
28	30	Biased	73.112	72.502	-0.6097
29	30	Unbiased	70.669	71.246	0.5767
30	20	Biased	70.743	74.063	3.32
31	30	Unbiased	73.982	70.263	-3.7192
33	30	Biased	71.481	74.653	3.1722
34	50	Unbiased	68.819	70.067	1.2482
35	20	Unbiased	72.702	72.888	0.1856
41	30	Biased	70.468	72.74	2.2721

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	70.102	72.165	73.85	1.8504	69.082	71.39	75.011	2.5727	-3.6429	-0.77557	1.4104	2.1539
20	68.689	71.388	73.851	1.5879	69.72	71.477	74.38	1.6786	-2.0824	0.08881	3.32	1.6912
30	70.33	71.886	73.982	1.3931	69.282	72.374	74.85	1.8953	-3.7192	0.48795	4.06	2.3477
50	68.819	70.865	74.21	1.958	70.067	72.514	74.111	1.2891	-0.5645	1.6486	4.6438	1.6197

Device Test: 28.22 TIMING|DELAY/CS/5/5/0/0/5/100kHz//@CS_ILIM_DELAY





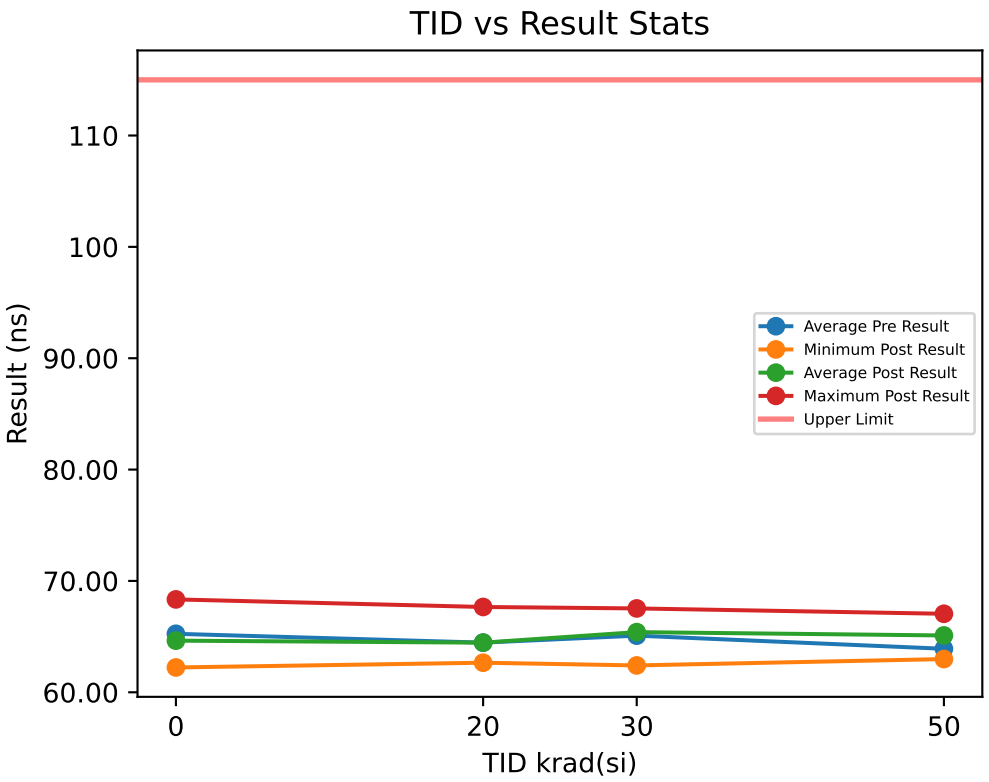
Test Results (Upper Limit = 115.0 (ns))

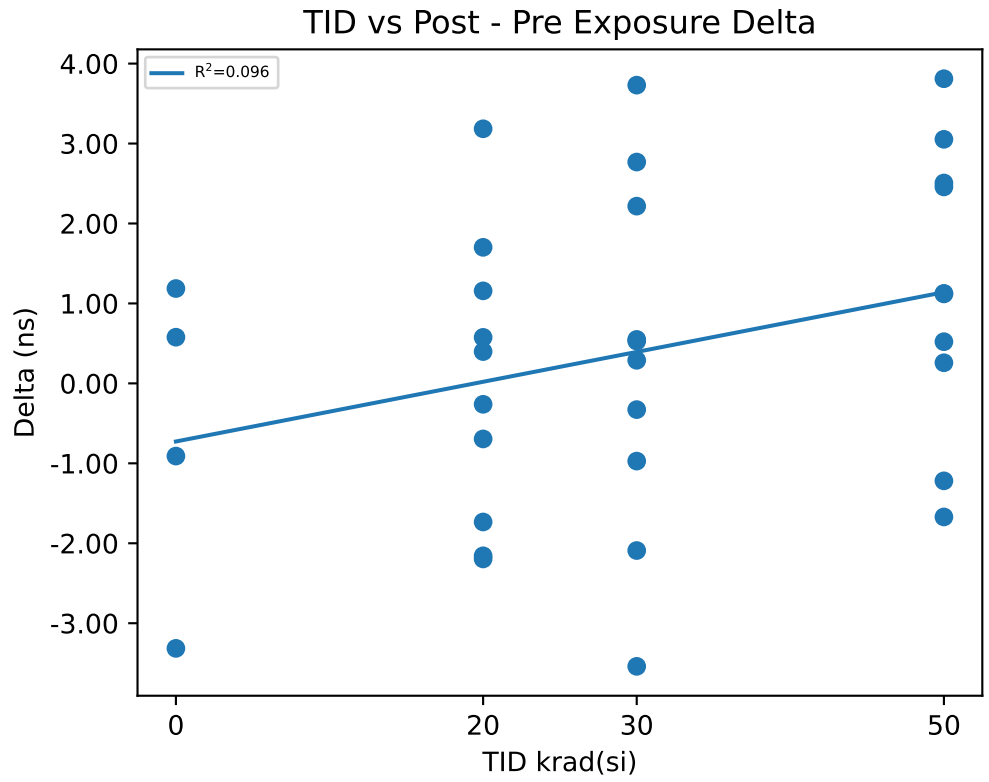
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	64.064	66.099	2.035
2	20	Unbiased	63.499	64.785	1.2852
3	50	Biased	66.867	66.325	-0.5424
4	30	Unbiased	65.134	65.846	0.7121
5	50	Unbiased	65.608	68.642	3.0343
6	30	Biased	65.38	69.481	4.1004
7	50	Biased	68.737	67.983	-0.754
8	30	Unbiased	66.185	64.141	-2.0438
9	20	Unbiased	64.533	65.784	1.2515
10	50	Biased	63.512	68.101	4.5886
11	30	Biased	67.562	68.303	0.7415
12	0	Correlation	68.425	69.416	0.9912
13	0	Correlation	65.73	65.873	0.1425
14	50	Unbiased	63.944	66.62	2.6751
15	20	Biased	68.39	69.231	0.8408
16	20	Unbiased	66.523	64.418	-2.1059
17	20	Biased	65.676	65.022	-0.6545
18	20	Unbiased	65.172	65.106	-0.0668
19	20	Biased	66.78	65.26	-1.5193
20	50	Unbiased	68.291	68.841	0.5501
21	0	Correlation	64.839	63.835	-1.0045
22	50	Unbiased	64.7	67.078	2.3774
23	0	Correlation	68.339	64.999	-3.3401
24	20	Biased	67.664	65.872	-1.7918
26	50	Biased	65.696	66.743	1.0467
27	30	Unbiased	68.788	68.097	-0.6903
28	30	Biased	67.5	67.195	-0.3046
29	30	Unbiased	65.654	66.052	0.3981
30	20	Biased	65.559	68.809	3.2503
31	30	Unbiased	68.294	65.138	-3.1557
33	30	Biased	66.053	69.079	3.0259
34	50	Unbiased	63.778	65.006	1.228
35	20	Unbiased	67.241	67.724	0.4829
41	30	Biased	64.957	67.172	2.2151

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	64.839	66.833	68.425	1.8252	63.835	66.031	69.416	2.4067	-3.3401	-0.80273	0.9912	1.8789
20	63.499	66.104	68.39	1.4976	64.418	66.201	69.231	1.74	-2.1059	0.09724	3.2503	1.6671
30	64.957	66.551	68.788	1.3772	64.141	67.05	69.481	1.7414	-3.1557	0.49987	4.1004	2.2185
50	63.512	65.52	68.737	1.892	65.006	67.144	68.841	1.2255	-0.754	1.6239	4.5886	1.6536

Device Test: 28.23 TIMING|DELAY/CS/12/12/0/0/5/100kHz//@CS_ILIM_DELAY





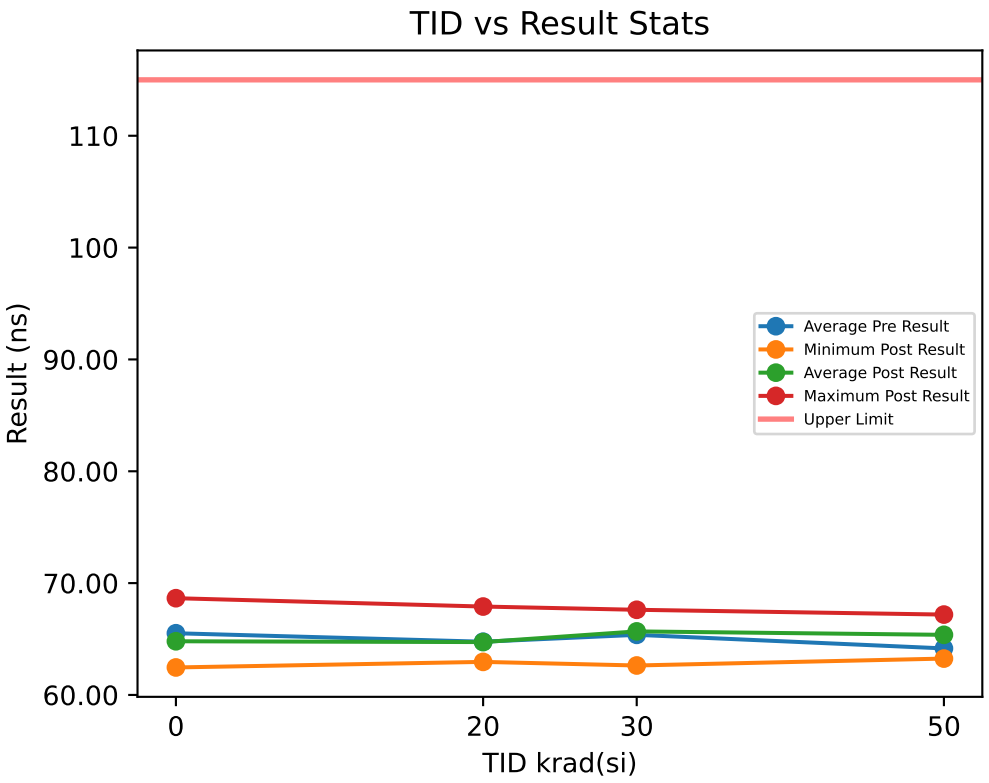
Test Results (Upper Limit = 115.0 (ns))

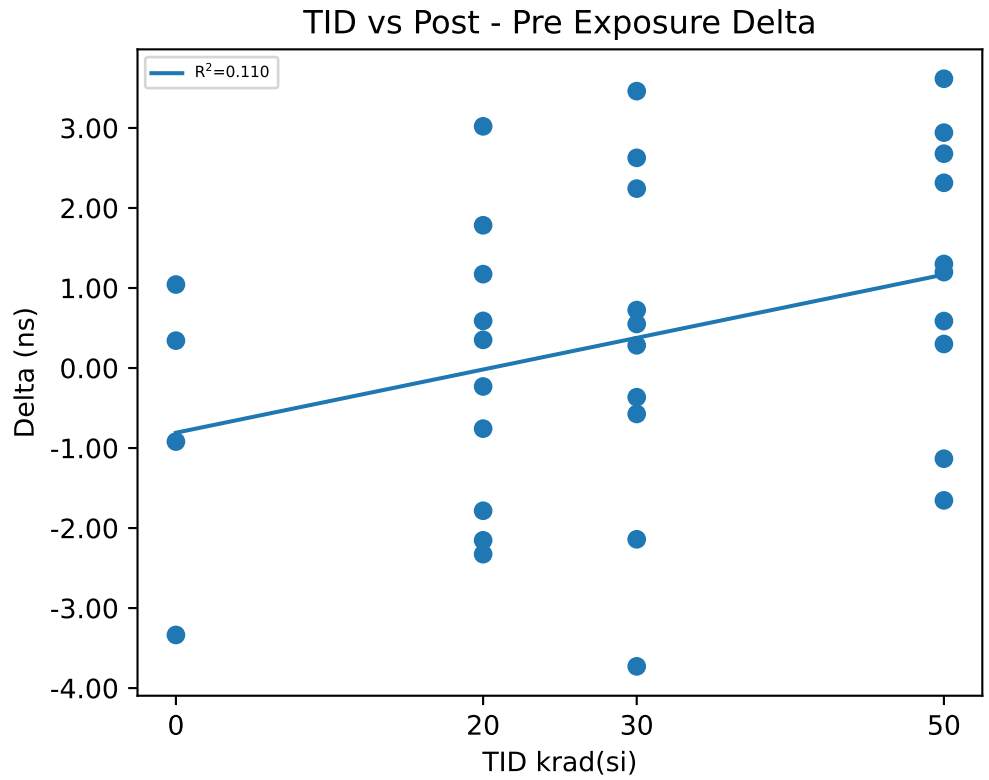
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	62.434	63.56	1.1256
2	20	Unbiased	61.801	62.958	1.1574
3	50	Biased	65.32	64.1	-1.2191
4	30	Unbiased	63.587	64.137	0.55
5	50	Unbiased	63.909	66.962	3.053
6	30	Biased	63.8	67.531	3.7306
7	50	Biased	67.194	65.523	-1.6707
8	30	Unbiased	64.503	62.412	-2.0908
9	20	Unbiased	62.963	64.665	1.7017
10	50	Biased	62.477	66.288	3.8106
11	30	Biased	66.216	66.504	0.2887
12	0	Correlation	67.154	68.341	1.1865
13	0	Correlation	63.98	64.558	0.5777
14	50	Unbiased	62.504	64.962	2.4573
15	20	Biased	67.085	67.661	0.5755
16	20	Unbiased	64.812	62.655	-2.1568
17	20	Biased	64.284	63.589	-0.6949
18	20	Unbiased	63.581	63.319	-0.2618
19	20	Biased	65.268	63.535	-1.7336
20	50	Unbiased	66.53	67.051	0.5213
21	0	Correlation	63.139	62.23	-0.9093
22	50	Unbiased	62.985	65.491	2.5068
23	0	Correlation	66.735	63.421	-3.3145
24	20	Biased	65.921	63.725	-2.1959
26	50	Biased	63.86	64.118	0.2579
27	30	Unbiased	67.24	66.912	-0.328
28	30	Biased	65.846	64.874	-0.9721
29	30	Unbiased	64.264	64.793	0.5292
30	20	Biased	63.565	66.75	3.1846
31	30	Unbiased	67.167	63.627	-3.5396
33	30	Biased	64.742	67.511	2.7687
34	50	Unbiased	61.865	62.984	1.1191
35	20	Unbiased	65.31	65.708	0.3978
41	30	Biased	63.503	65.72	2.2169

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	63.139	65.252	67.154	1.9917	62.23	64.637	68.341	2.6456	-3.3145	-0.6149	1.1865	2.0035
20	61.801	64.459	67.085	1.5436	62.655	64.457	67.661	1.7015	-2.1959	-0.0026	3.1846	1.7606
30	63.503	65.087	67.24	1.4283	62.412	65.402	67.531	1.7292	-3.5396	0.31536	3.7306	2.2141
50	61.865	63.908	67.194	1.8524	62.984	65.104	67.051	1.4083	-1.6707	1.1962	3.8106	1.7948

Device Test: 28.24 TIMING|DELAY/CS/14/14/0/0/5/100kHz//@CS_ILIM_DELAY





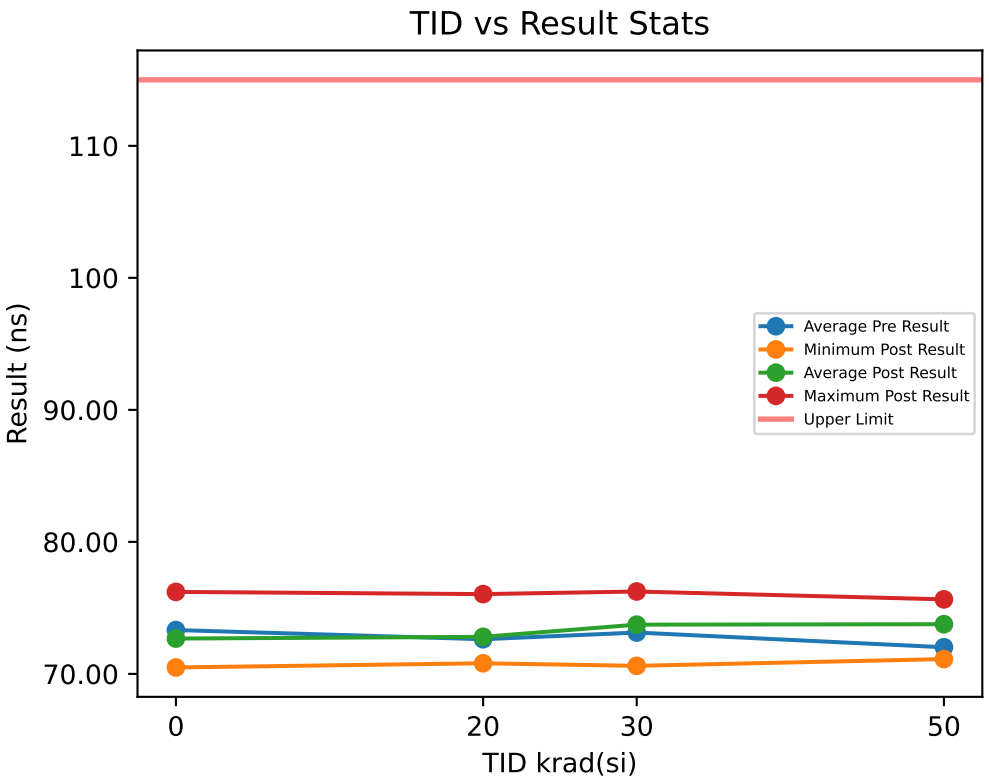
Test Results (Upper Limit = 115.0 (ns))

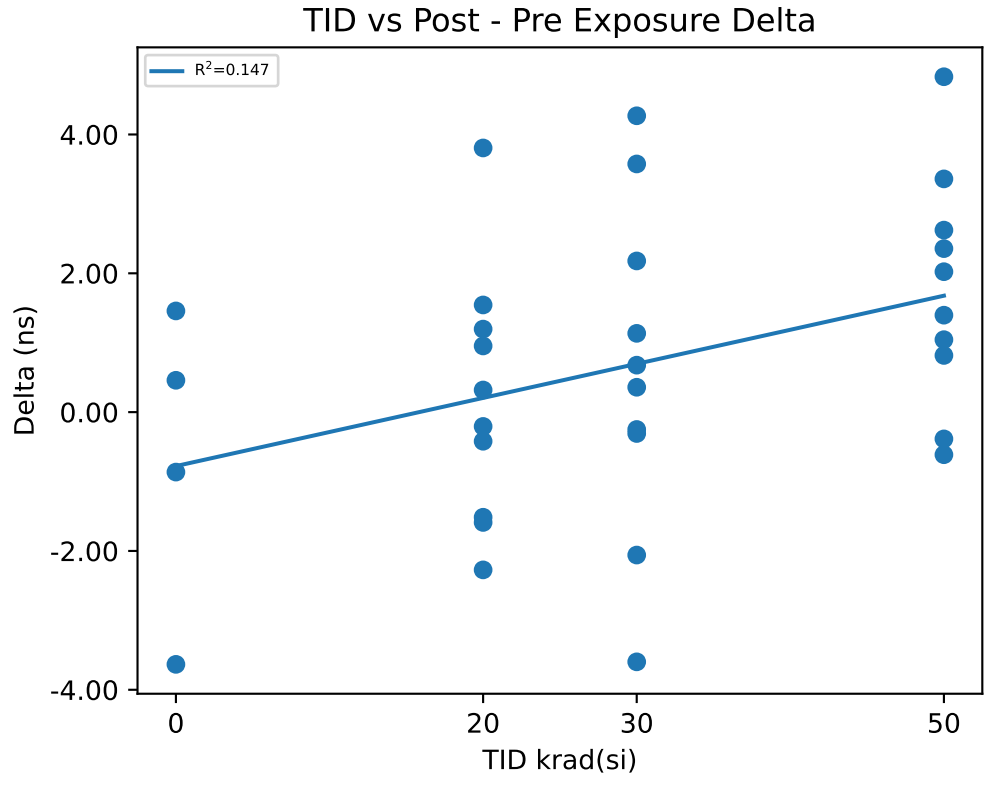
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	62.541	63.841	1.3001
2	20	Unbiased	62.141	63.314	1.1732
3	50	Biased	65.586	64.453	-1.1335
4	30	Unbiased	63.913	64.197	0.2836
5	50	Unbiased	64.243	67.185	2.9416
6	30	Biased	64.15	67.611	3.4604
7	50	Biased	67.34	65.686	-1.654
8	30	Unbiased	64.775	62.634	-2.1405
9	20	Unbiased	63.254	65.038	1.7839
10	50	Biased	62.745	66.36	3.6152
11	30	Biased	66.501	67.225	0.724
12	0	Correlation	67.607	68.65	1.0435
13	0	Correlation	64.236	64.579	0.3421
14	50	Unbiased	62.826	65.505	2.6784
15	20	Biased	67.316	67.904	0.5889
16	20	Unbiased	65.283	62.956	-2.3263
17	20	Biased	64.523	63.765	-0.7575
18	20	Unbiased	63.904	63.673	-0.2308
19	20	Biased	65.536	63.752	-1.7839
20	50	Unbiased	66.886	67.187	0.3004
21	0	Correlation	63.377	62.458	-0.9195
22	50	Unbiased	63.292	65.606	2.3147
23	0	Correlation	66.847	63.511	-3.336
24	20	Biased	66.144	63.99	-2.1533
26	50	Biased	64.097	64.684	0.5869
27	30	Unbiased	67.605	67.241	-0.3647
28	30	Biased	66.014	65.44	-0.5741
29	30	Unbiased	64.544	65.094	0.5506
30	20	Biased	63.88	66.9	3.0204
31	30	Unbiased	67.416	63.687	-3.7284
33	30	Biased	64.988	67.615	2.6266
34	50	Unbiased	62.053	63.252	1.1985
35	20	Unbiased	65.617	65.969	0.3521
41	30	Biased	63.839	66.081	2.2421

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	63.377	65.517	67.607	2.0292	62.458	64.799	68.65	2.7094	-3.336	-0.71747	1.0435	1.9254
20	62.141	64.76	67.316	1.5183	62.956	64.726	67.904	1.6705	-2.3263	-0.03333	3.0204	1.7638
30	63.839	65.375	67.605	1.4146	62.634	65.682	67.615	1.7733	-3.7284	0.30796	3.4604	2.1809
50	62.053	64.161	67.34	1.8614	63.252	65.376	67.187	1.3285	-1.654	1.2148	3.6152	1.7346

Device Test: 28.25 TIMING|DELAY/CS/4.5/4.5/0/1000/4.5/100kHz//@CS_ILIM_DELAY





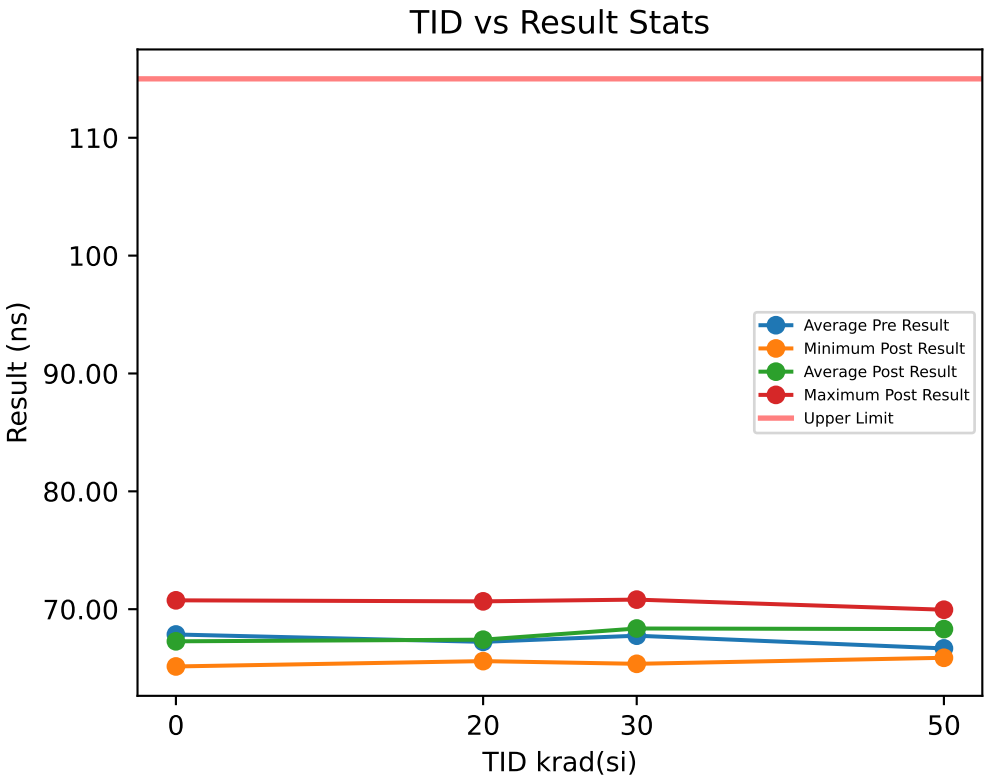
Test Results (Upper Limit = 115.0 (ns))

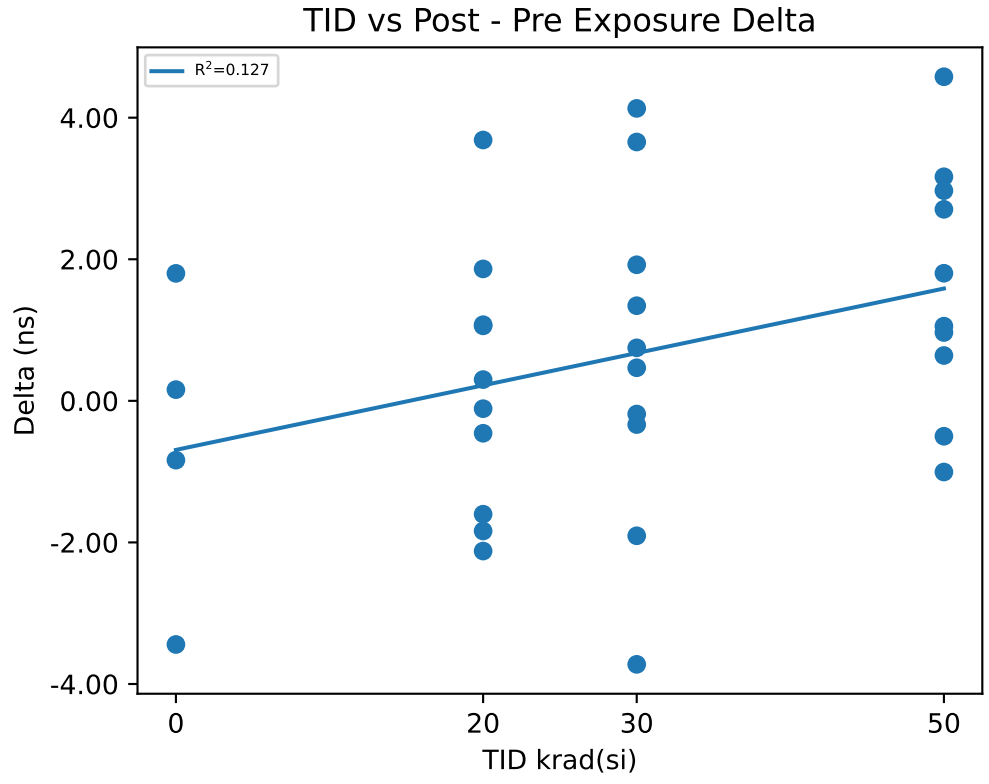
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	70.351	72.374	2.0232
2	20	Unbiased	70.041	71.237	1.1962
3	50	Biased	73.287	72.674	-0.6135
4	30	Unbiased	71.499	72.176	0.6767
5	50	Unbiased	72.012	75.372	3.3601
6	30	Biased	71.971	76.24	4.2694
7	50	Biased	75.335	74.949	-0.3857
8	30	Unbiased	72.669	70.61	-2.059
9	20	Unbiased	70.884	72.428	1.544
10	50	Biased	70.343	75.175	4.8319
11	30	Biased	74.1	75.235	1.1349
12	0	Correlation	74.752	76.21	1.4579
13	0	Correlation	72.112	72.571	0.4587
14	50	Unbiased	70.522	73.144	2.6223
15	20	Biased	75.09	76.044	0.9535
16	20	Unbiased	73.077	70.804	-2.2727
17	20	Biased	72.26	71.841	-0.4197
18	20	Unbiased	71.841	71.634	-0.2061
19	20	Biased	73.063	71.548	-1.5144
20	50	Unbiased	74.83	75.647	0.8167
21	0	Correlation	71.351	70.487	-0.8638
22	50	Unbiased	71.259	73.615	2.3557
23	0	Correlation	75.072	71.438	-3.6338
24	20	Biased	73.924	72.334	-1.5893
26	50	Biased	72.159	73.556	1.3967
27	30	Unbiased	75.422	75.114	-0.3078
28	30	Biased	74.074	73.824	-0.2499
29	30	Unbiased	71.954	72.312	0.3584
30	20	Biased	72.027	75.832	3.8059
31	30	Unbiased	75.231	71.633	-3.5976
33	30	Biased	72.511	76.086	3.5754
34	50	Unbiased	70.078	71.121	1.0438
35	20	Unbiased	74.05	74.369	0.3189
41	30	Biased	71.888	74.066	2.1781

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	71.351	73.322	75.072	1.8671	70.487	72.677	76.21	2.5051	-3.6338	-0.64525	1.4579	2.2076
20	70.041	72.626	75.09	1.5277	70.804	72.807	76.044	1.9093	-2.2727	0.18163	3.8059	1.8007
30	71.499	73.132	75.422	1.4537	70.61	73.73	76.24	1.9638	-3.5976	0.59786	4.2694	2.3897
50	70.078	72.018	75.335	1.9062	71.121	73.763	75.647	1.4937	-0.6135	1.7451	4.8319	1.6645

Device Test: 28.26 TIMING|DELAY/CS/5/5/0/1000/5/100kHz//@CS_ILIM_DELAY





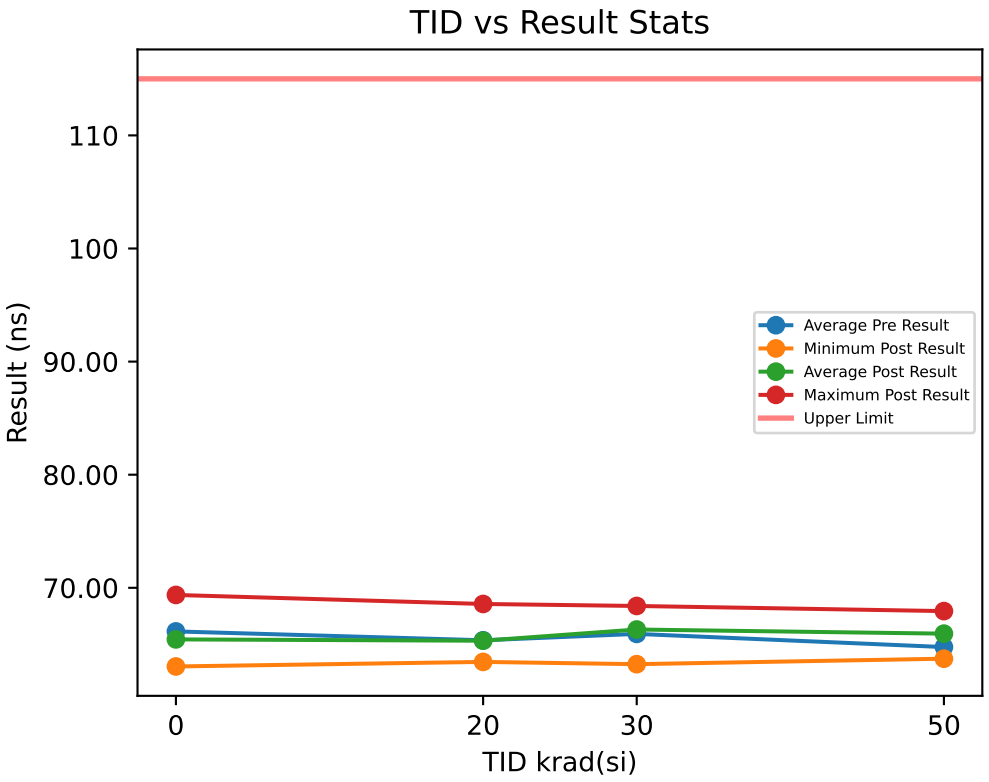
Test Results (Upper Limit = 115.0 (ns))

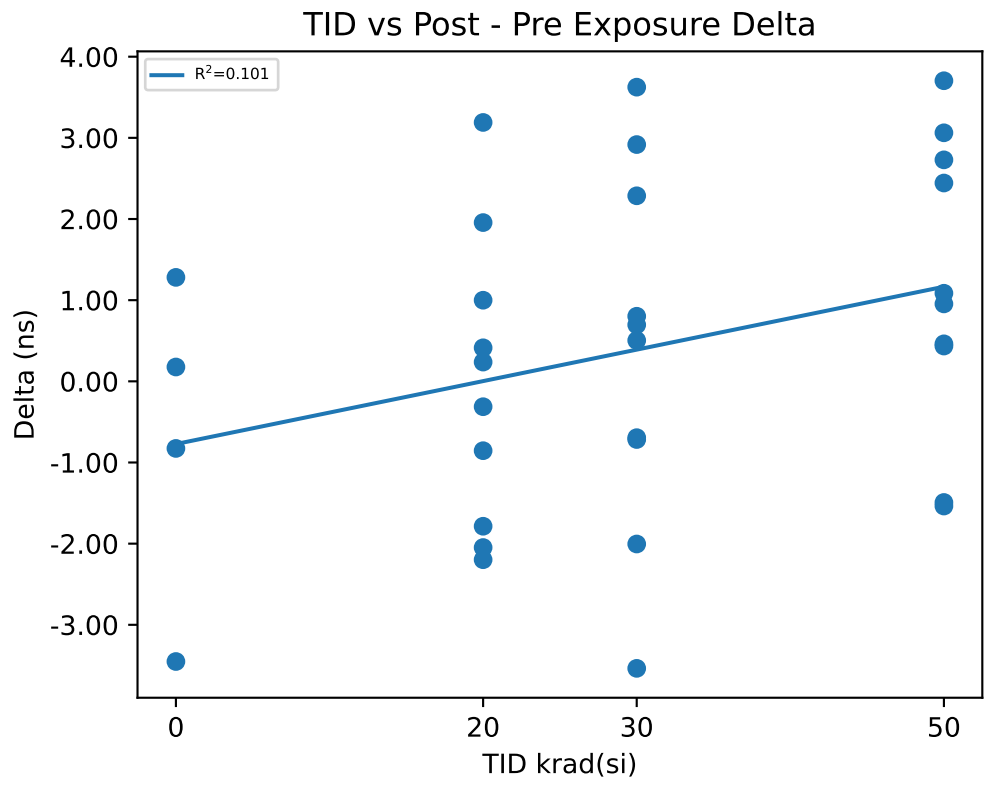
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	65.063	66.865	1.8025
2	20	Unbiased	64.731	65.806	1.0757
3	50	Biased	67.938	67.438	-0.5
4	30	Unbiased	66.256	67.005	0.7487
5	50	Unbiased	66.662	69.827	3.1652
6	30	Biased	66.627	70.758	4.1312
7	50	Biased	69.946	68.94	-1.0054
8	30	Unbiased	67.271	65.365	-1.9062
9	20	Unbiased	65.362	67.225	1.8638
10	50	Biased	65.044	69.623	4.5784
11	30	Biased	68.584	69.928	1.3438
12	0	Correlation	68.951	70.751	1.8007
13	0	Correlation	66.95	67.108	0.1585
14	50	Unbiased	65.021	67.99	2.9694
15	20	Biased	69.606	70.665	1.0593
16	20	Unbiased	67.716	65.594	-2.122
17	20	Biased	66.873	66.415	-0.458
18	20	Unbiased	66.358	66.248	-0.1107
19	20	Biased	67.974	66.373	-1.6012
20	50	Unbiased	69.314	69.955	0.6406
21	0	Correlation	65.978	65.141	-0.8379
22	50	Unbiased	65.969	68.675	2.7055
23	0	Correlation	69.537	66.095	-3.4417
24	20	Biased	68.504	66.665	-1.8387
26	50	Biased	66.856	67.911	1.0551
27	30	Unbiased	69.781	69.595	-0.1863
28	30	Biased	68.575	68.24	-0.335
29	30	Unbiased	66.794	67.261	0.4675
30	20	Biased	66.575	70.26	3.6849
31	30	Unbiased	69.853	66.13	-3.7225
33	30	Biased	67.156	70.812	3.6565
34	50	Unbiased	64.911	65.876	0.9653
35	20	Unbiased	68.57	68.87	0.3003
41	30	Biased	66.601	68.524	1.9223

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	65.978	67.854	69.537	1.6704	65.141	67.274	70.751	2.4537	-3.4417	-0.5801	1.8007	2.1961
20	64.731	67.227	69.606	1.5241	65.594	67.412	70.665	1.8476	-2.122	0.18534	3.6849	1.818
30	66.256	67.75	69.853	1.3431	65.365	68.362	70.812	1.9083	-3.7225	0.612	4.1312	2.3713
50	64.911	66.672	69.946	1.8528	65.876	68.31	69.955	1.3455	-1.0054	1.6377	4.5784	1.7405

Device Test: 28.27 TIMING|DELAY/CS/12/12/0/1000/5/100kHz//@CS_ILIM_DELAY





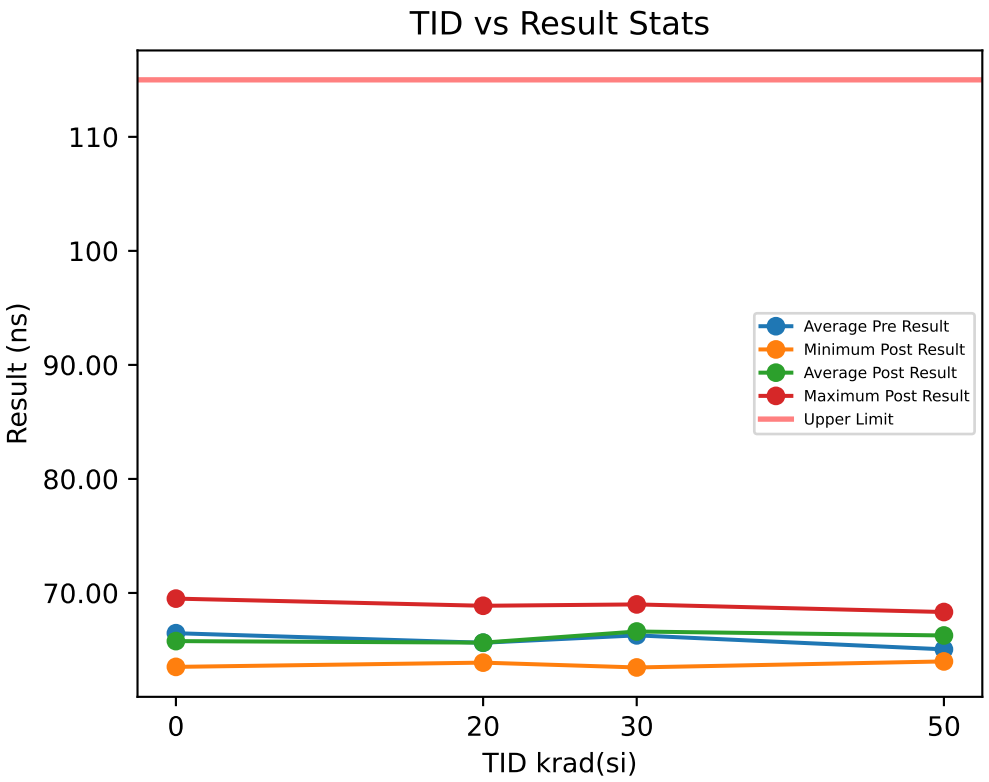
Test Results (Upper Limit = 115.0 (ns))

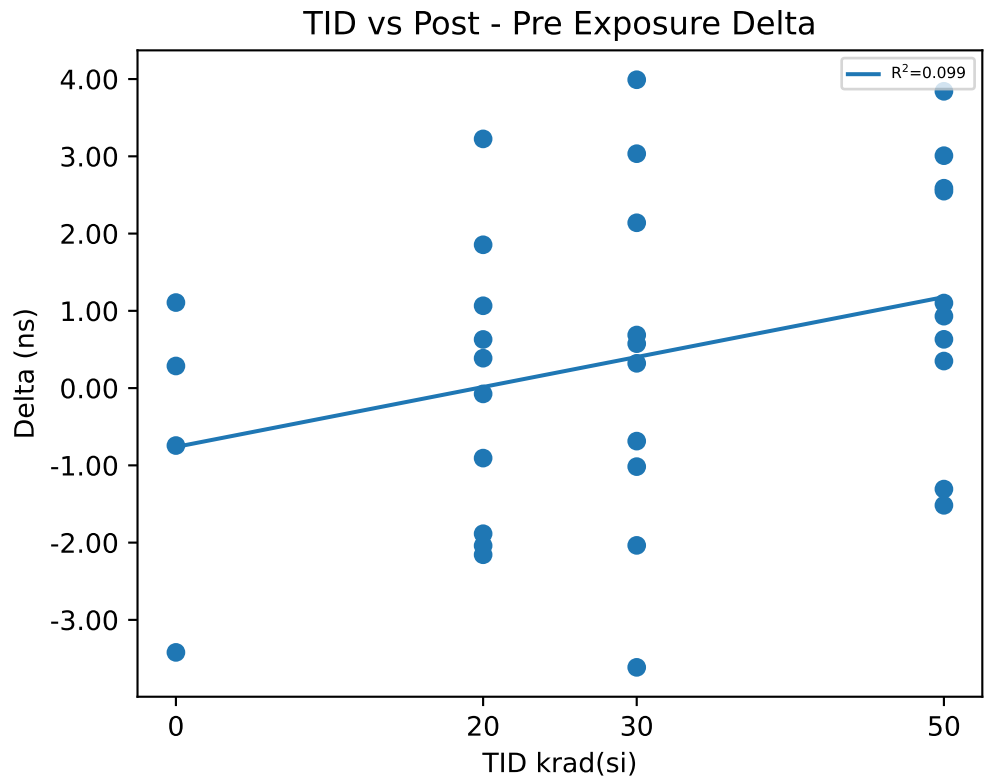
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	63.33	64.415	1.0854
2	20	Unbiased	62.675	63.675	0.9994
3	50	Biased	66.23	64.694	-1.5365
4	30	Unbiased	64.535	65.231	0.6964
5	50	Unbiased	64.88	67.942	3.0622
6	30	Biased	64.745	68.37	3.6246
7	50	Biased	67.883	66.391	-1.4925
8	30	Unbiased	65.253	63.248	-2.0042
9	20	Unbiased	63.816	65.772	1.9561
10	50	Biased	63.366	67.07	3.7037
11	30	Biased	66.966	67.768	0.8019
12	0	Correlation	68.088	69.369	1.2809
13	0	Correlation	64.972	65.149	0.1766
14	50	Unbiased	63.354	65.797	2.4435
15	20	Biased	68.334	68.571	0.2372
16	20	Unbiased	65.647	63.45	-2.1978
17	20	Biased	65.138	64.283	-0.8546
18	20	Unbiased	64.528	64.215	-0.3127
19	20	Biased	65.961	64.176	-1.7855
20	50	Unbiased	67.307	67.769	0.462
21	0	Correlation	63.874	63.047	-0.8267
22	50	Unbiased	63.789	66.517	2.7289
23	0	Correlation	67.644	64.192	-3.4521
24	20	Biased	66.814	64.766	-2.0478
26	50	Biased	64.701	65.136	0.4348
27	30	Unbiased	68.166	67.472	-0.6941
28	30	Biased	66.568	65.851	-0.7168
29	30	Unbiased	64.933	65.437	0.504
30	20	Biased	64.54	67.729	3.1898
31	30	Unbiased	68.007	64.47	-3.5365
33	30	Biased	65.478	68.395	2.9173
34	50	Unbiased	62.779	63.733	0.9541
35	20	Unbiased	66.167	66.58	0.4132
41	30	Biased	64.599	66.885	2.2861

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	63.874	66.145	68.088	2.0462	63.047	65.439	69.369	2.7573	-3.4521	-0.70532	1.2809	2.0234
20	62.675	65.362	68.334	1.6006	63.45	65.322	68.571	1.7728	-2.1978	-0.04027	3.1898	1.7717
30	64.535	65.925	68.166	1.3974	63.248	66.313	68.395	1.7414	-3.5365	0.38787	3.6246	2.2179
50	62.779	64.762	67.883	1.8029	63.733	65.946	67.942	1.4368	-1.5365	1.1846	3.7037	1.8123

Device Test: 28.28 TIMING|DELAY/CS/14/14/0/1000/5/100kHz//@CS_ILIM_DELAY





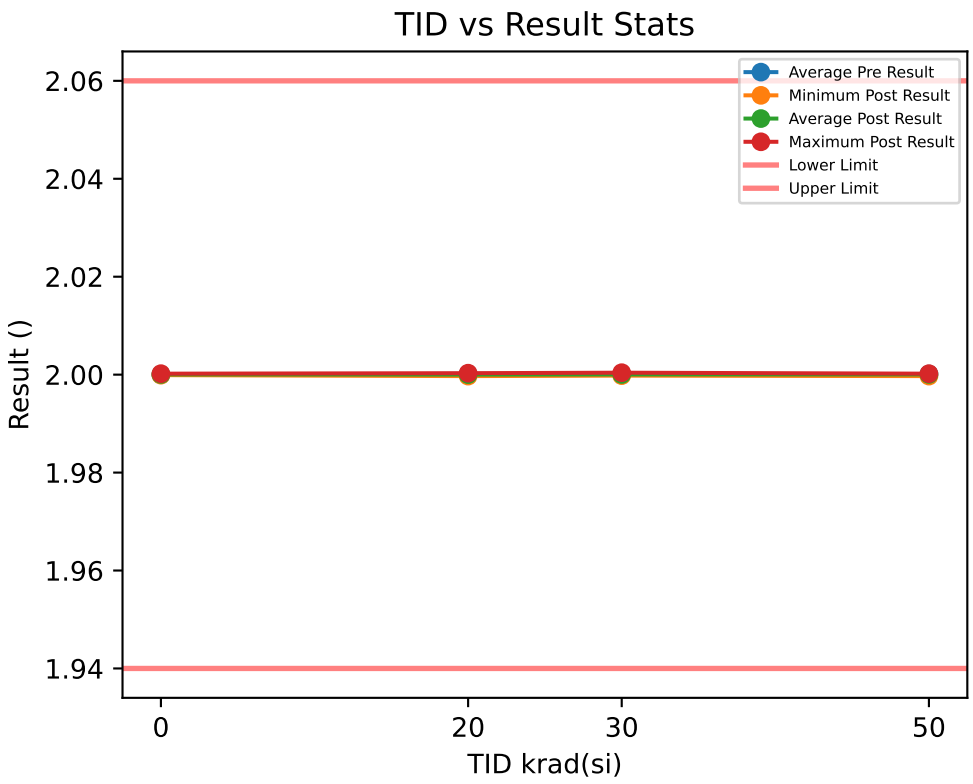
Test Results (Upper Limit = 115.0 (ns))

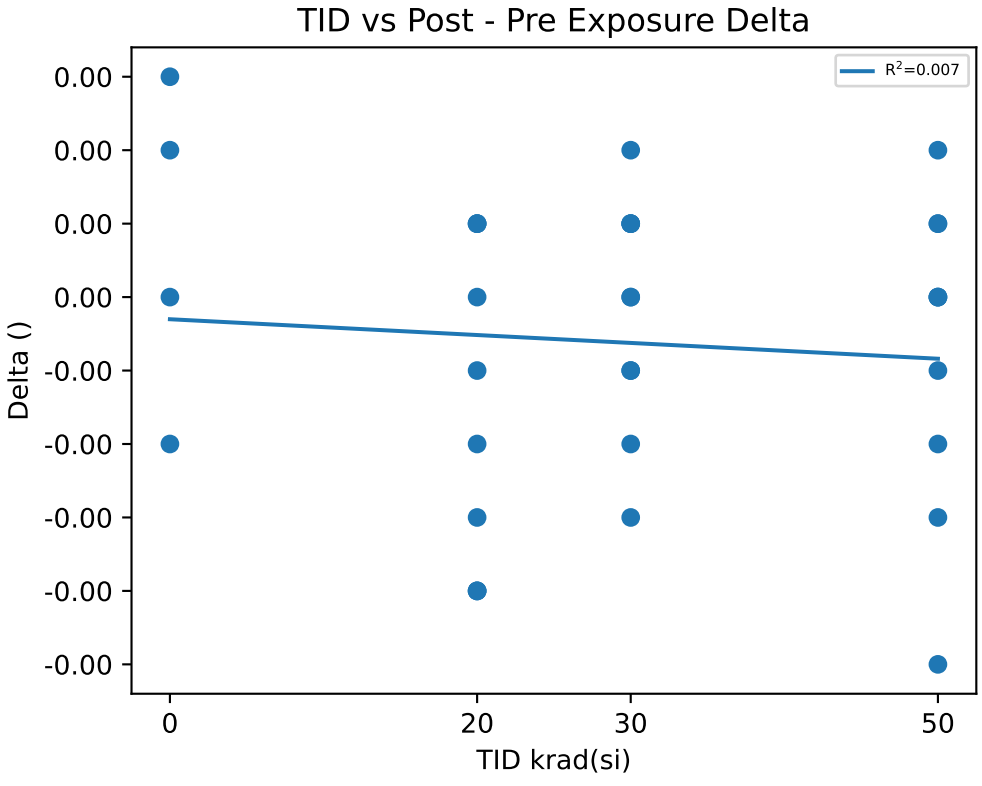
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	63.622	64.553	0.931
2	20	Unbiased	62.91	63.976	1.0657
3	50	Biased	66.478	65.171	-1.3072
4	30	Unbiased	64.785	65.106	0.3207
5	50	Unbiased	65.057	68.066	3.0083
6	30	Biased	65.004	68.996	3.9912
7	50	Biased	68.33	66.813	-1.5172
8	30	Unbiased	65.502	63.467	-2.0357
9	20	Unbiased	64.047	65.902	1.855
10	50	Biased	63.601	67.442	3.8414
11	30	Biased	67.544	68.231	0.6871
12	0	Correlation	68.397	69.504	1.1073
13	0	Correlation	65.298	65.584	0.2862
14	50	Unbiased	63.676	66.263	2.5871
15	20	Biased	68.49	68.877	0.387
16	20	Unbiased	65.929	63.89	-2.0394
17	20	Biased	65.517	64.611	-0.9061
18	20	Unbiased	64.646	64.571	-0.0751
19	20	Biased	66.364	64.479	-1.8849
20	50	Unbiased	67.696	68.328	0.6313
21	0	Correlation	64.26	63.517	-0.7435
22	50	Unbiased	64.212	66.76	2.549
23	0	Correlation	67.928	64.508	-3.4208
24	20	Biased	67.164	65.007	-2.1569
26	50	Biased	64.982	65.332	0.3501
27	30	Unbiased	68.55	67.864	-0.6862
28	30	Biased	66.967	65.951	-1.0164
29	30	Unbiased	65.377	65.952	0.5751
30	20	Biased	64.819	68.045	3.2255
31	30	Unbiased	68.313	64.699	-3.6145
33	30	Biased	65.754	68.788	3.034
34	50	Unbiased	62.895	63.996	1.101
35	20	Unbiased	66.444	67.073	0.6297
41	30	Biased	65.009	67.149	2.1399

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	64.26	66.471	68.397	2.0081	63.517	65.778	69.504	2.6235	-3.4208	-0.6927	1.1073	1.9701
20	62.91	65.633	68.49	1.6112	63.89	65.643	68.877	1.769	-2.1569	0.01005	3.2255	1.7863
30	64.785	66.281	68.55	1.4351	63.467	66.62	68.996	1.8735	-3.6145	0.33952	3.9912	2.3137
50	62.895	65.055	68.33	1.8613	63.996	66.272	68.328	1.4748	-1.5172	1.2175	3.8414	1.7884

Device Test: 28.3 LEVEL|RATIO/CS/12/12/0/0/5/500kHz//@C_CS_R





Test Results (Lower Limit = 1.94, Upper Limit = 2.06 ())

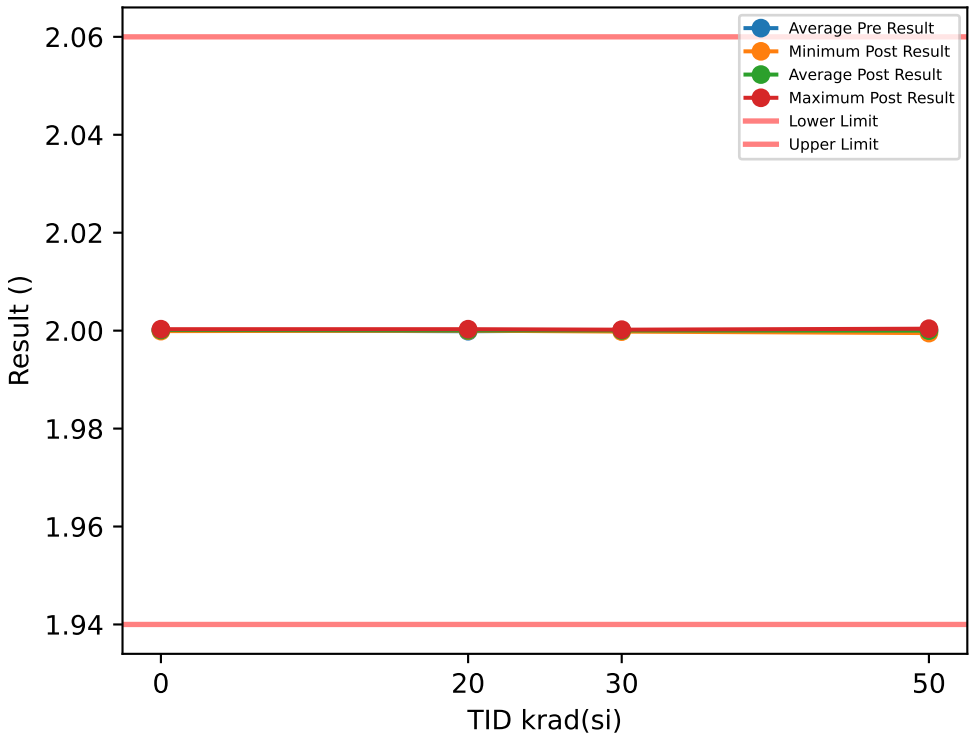
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	2.0001	2.0001	0
2	20	Unbiased	2.0004	2	-0.0004
3	50	Biased	2	2.0001	0.0001
4	30	Unbiased	2	2.0001	0.0001
5	50	Unbiased	2.0001	2.0001	0
6	30	Biased	2.0001	2.0001	0
7	50	Biased	1.9999	2.0001	0.0002
8	30	Unbiased	1.9998	1.9999	0.0001
9	20	Unbiased	2.0001	1.9998	-0.0003
10	50	Biased	2	1.9999	-0.0001
11	30	Biased	2	2.0001	0.0001
12	0	Correlation	1.9999	2.0001	0.0002
13	0	Correlation	2	2	0
14	50	Unbiased	2.0004	2.0002	-0.0002
15	20	Biased	1.9999	2	0.0001
16	20	Unbiased	2.0001	2.0001	0
17	20	Biased	2.0001	1.9997	-0.0004
18	20	Unbiased	2.0002	2.0003	0.0001
19	20	Biased	2.0003	2.0001	-0.0002
20	50	Unbiased	2.0001	2.0001	0
21	0	Correlation	2.0001	1.9999	-0.0002
22	50	Unbiased	2.0001	2.0002	0.0001
23	0	Correlation	1.9999	2.0002	0.0003
24	20	Biased	2	2.0001	0.0001
26	50	Biased	2	1.9997	-0.0003
27	30	Unbiased	2.0006	2.0004	-0.0002
28	30	Biased	1.9998	2	0.0002
29	30	Unbiased	2.0001	2	-0.0001
30	20	Biased	2.0001	2	-0.0001
31	30	Unbiased	2	2	0
33	30	Biased	2.0001	1.9998	-0.0003
34	50	Unbiased	2.0005	2	-0.0005
35	20	Unbiased	2.0004	2	-0.0004
41	30	Biased	2.0001	2	-0.0001

Test Statistics ()

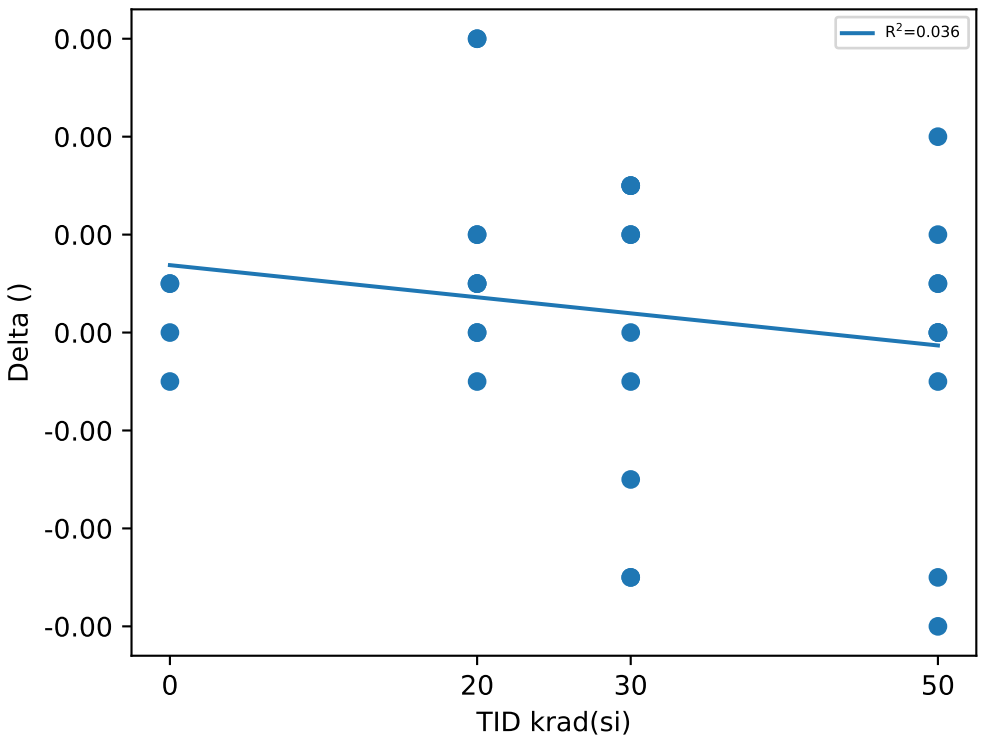
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.9999	2	2.0001	9.5743e-05	1.9999	2	2.0002	0.0001291	-0.0002	7.5e-05	0.0003	0.00022174
20	1.9999	2.0002	2.0004	0.00016465	1.9997	2	2.0003	0.00016633	-0.0004	-0.00015	0.0001	0.00021731
30	1.9998	2.0001	2.0006	0.00022211	1.9998	2	2.0004	0.00015776	-0.0003	-2e-05	0.0002	0.00015492
50	1.9999	2.0001	2.0005	0.00018738	1.9997	2.0001	2.0002	0.00015092	-0.0005	-7e-05	0.0002	0.00021108

Device Test: 28.4 LEVEL|RATIO/CS/14/14/0/0/5/500kHz//@C_CS_R

TID vs Result Stats



TID vs Post - Pre Exposure Delta



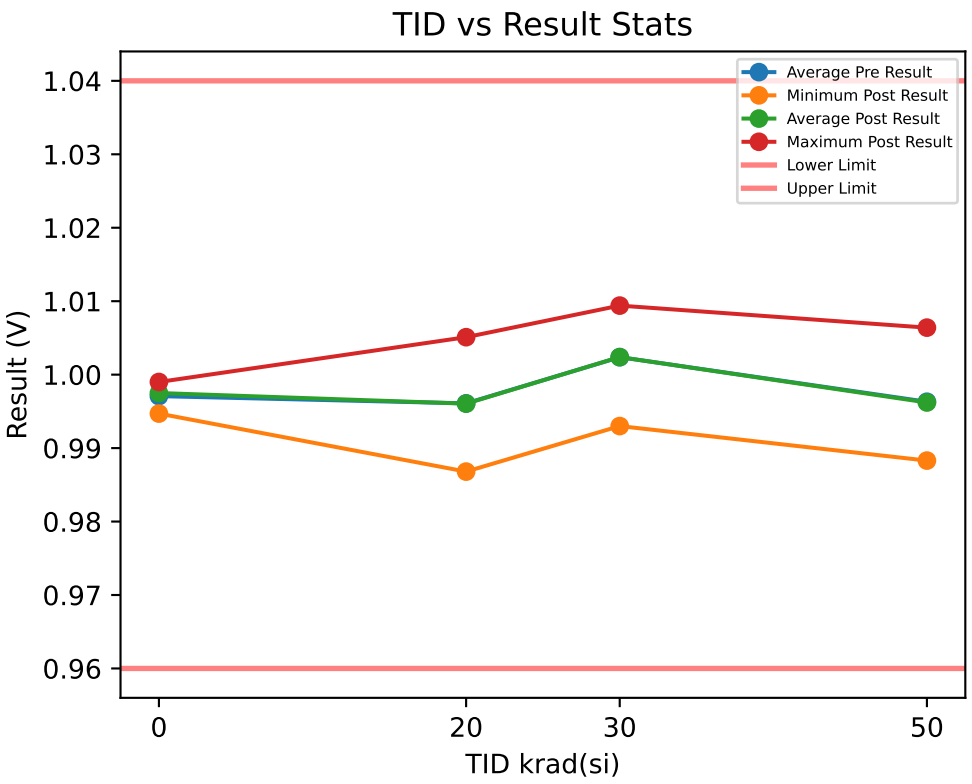
Test Results (Lower Limit = 1.94, Upper Limit = 2.06 ())

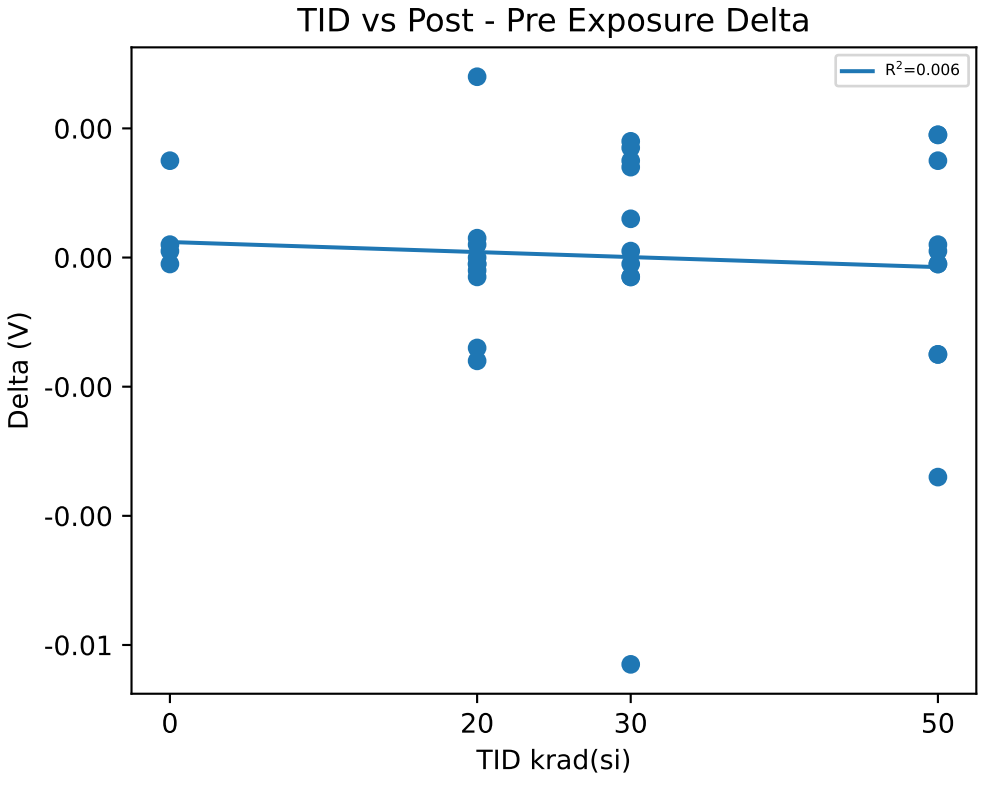
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	2	2.0001	0.0001
2	20	Unbiased	1.9994	2	0.0006
3	50	Biased	1.9999	2	0.0001
4	30	Unbiased	2	1.9999	-0.0001
5	50	Unbiased	2.0001	2.0001	0
6	30	Biased	1.9998	2.0001	0.0003
7	50	Biased	2.0001	2	-0.0001
8	30	Unbiased	1.9999	2.0001	0.0002
9	20	Unbiased	2	2.0001	0.0001
10	50	Biased	2.0001	2.0001	0
11	30	Biased	2.0003	1.9998	-0.0005
12	0	Correlation	2.0002	2.0003	0.0001
13	0	Correlation	2	1.9999	-0.0001
14	50	Unbiased	2	2.0004	0.0004
15	20	Biased	2	2	0
16	20	Unbiased	1.9999	2	0.0001
17	20	Biased	2.0001	2.0003	0.0002
18	20	Unbiased	1.9999	2.0001	0.0002
19	20	Biased	2	2	0
20	50	Unbiased	1.9999	2.0001	0.0002
21	0	Correlation	2.0001	2.0002	0.0001
22	50	Unbiased	2.0001	1.9995	-0.0006
23	0	Correlation	2.0001	2.0001	0
24	20	Biased	1.9999	2	0.0001
26	50	Biased	2.0001	1.9996	-0.0005
27	30	Unbiased	2.0003	2	-0.0003
28	30	Biased	1.9998	2.0001	0.0003
29	30	Unbiased	2.0001	2.0001	0
30	20	Biased	1.9995	2.0001	0.0006
31	30	Unbiased	1.9999	2.0002	0.0003
33	30	Biased	2	2.0002	0.0002
34	50	Unbiased	2.0001	2.0001	0
35	20	Unbiased	2.0001	2	-0.0001
41	30	Biased	2.0004	1.9999	-0.0005

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2	2.0001	2.0002	8.165e-05	1.9999	2.0001	2.0003	0.00017078	-0.0001	2.5e-05	0.0001	9.5743e-05
20	1.9994	1.9999	2.0001	0.00023944	2	2.0001	2.0003	9.6609e-05	-0.0001	0.00018	0.0006	0.00023944
30	1.9998	2.0001	2.0004	0.00021731	1.9998	2	2.0002	0.00013499	-0.0005	-1e-05	0.0003	0.00032472
50	1.9999	2	2.0001	8.4327e-05	1.9995	2	2.0004	0.00026247	-0.0006	-4e-05	0.0004	0.00030258

Device Test: 28.9 VOLTAGE|OC/CS/4.5/4.5/0/0/4.5/100kHz//@V_CS_ILIM_OC





Test Results (Lower Limit = 0.96, Upper Limit = 1.04 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	50	Biased	0.9945	0.9944	-0.0001
2	20	Unbiased	0.9884	0.9868	-0.0016
3	50	Biased	0.994	0.9959	0.0019
4	30	Unbiased	0.9929	0.993	0.0001
5	50	Unbiased	0.9944	0.9945	0.0001
6	30	Biased	1.008	1.0094	0.0014
7	50	Biased	0.9943	0.9945	0.0002
8	30	Unbiased	0.9974	0.9992	0.0018
9	20	Unbiased	0.9897	0.9899	0.0002
10	50	Biased	0.9884	0.9883	-0.0001
11	30	Biased	1.0004	1.0019	0.0015
12	0	Correlation	0.9975	0.999	0.0015
13	0	Correlation	0.999	0.9989	-0.0001
14	50	Unbiased	0.9975	0.9941	-0.0034
15	20	Biased	1.0021	1.0019	-0.0002
16	20	Unbiased	1.0004	1.0003	-0.0001
17	20	Biased	0.9914	0.9942	0.0028
18	20	Unbiased	0.9975	0.9978	0.0003
19	20	Biased	0.9928	0.9928	0
20	50	Unbiased	1.0049	1.0064	0.0015
21	0	Correlation	0.9945	0.9947	0.0002
22	50	Unbiased	0.9989	0.9974	-0.0015
23	0	Correlation	0.9973	0.9974	0.0001
24	20	Biased	0.996	0.9959	-0.0001
26	50	Biased	1.0018	1.0037	0.0019
27	30	Unbiased	1.0066	1.0063	-0.0003
28	30	Biased	1.0095	1.0094	-0.0001
29	30	Unbiased	1.0051	1.0048	-0.0003
30	20	Biased	1.0065	1.0051	-0.0014
31	30	Unbiased	1.0047	1.0053	0.0006
33	30	Biased	0.9989	1.0006	0.0017
34	50	Unbiased	0.9944	0.9929	-0.0015
35	20	Unbiased	0.9961	0.9958	-0.0003
41	30	Biased	1.0003	0.994	-0.0063

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.9945	0.99708	0.999	0.0018768	0.9947	0.9975	0.999	0.002005	-0.0001	0.000425	0.0015	0.00072744
20	0.9884	0.99609	1.0065	0.0057528	0.9868	0.99605	1.0051	0.0055247	-0.0016	-4e-05	0.0028	0.0011843
30	0.9929	1.0024	1.0095	0.0052482	0.993	1.0024	1.0094	0.0057738	-0.0063	1e-05	0.0018	0.0023709
50	0.9884	0.99631	1.0049	0.0046496	0.9883	0.99621	1.0064	0.0052551	-0.0034	-0.0001	0.0019	0.0016833

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Last updated 10/2025